DATABOOK 1991-1992

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Supertex Inc. Life Support Policy

As a general policy, Supertex Inc. does not recommend the use of any of its products in any of the following: (a) life support applications where the failure or malfunction of the Supertex product can be reasonably expected to cause failure of the life support device or to significantly affect its safety or effectiveness, or (b) any nuclear facility. Supertex will not knowingly sell its products for use in such applications unless it receives an adequate "products liability indemnification insurance agreement", satisfactory to Supertex, stating that the risks of injury or damage have been minimized, that the customer assumes all such risks, and that the liability of Supertex is adequately covered in the customer's insurance policy.

Examples of devices considered to be life support devices are neonatal oxygen analyzers, nerve stimulators (for any use), autotransfusion devices, blood pumps, defibrillators, arrhythmia detectors and alarms, pacemakers, hemodialysis systems, peritoneal dialysis systems, ventilators of all types, infusion pumps, and any other devices designated as "critical" by the FDA. The above are representative examples only and are not intended to be conclusive or exclusive of any other life support device.

Examples of nuclear facility applications are applications in (a) a nuclear reactor, or (b) any device designed or used in connection with the handling, processing, packaging, preparation, utilization, fabrication, alloying, storing or disposal of fissionable material or waste products thereof.

General

This catalog has been carefully checked and is believed to be reliable; however, no responsibility is assumed for possible omissions or inaccuracies. Specifications are subject to change without notice.

Supertex cannot assume responsibility for use of circuitry described; no circuit patent licenses are implied; and Supertex reserves the right to change said circuity at any time without notice. Liability of Supertex to circuits it manufactures is limited to the replacement of such circuits if they are determined to be defective due to workmanship and not due to misuse or mishandling.

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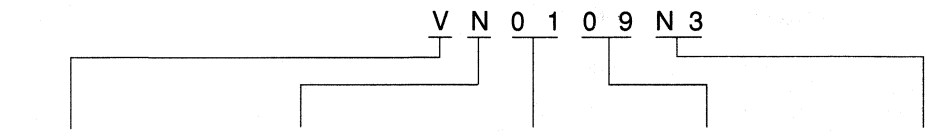
Alphanumeric Index

Supertex inc.

Product Nomenclature/Ordering Information

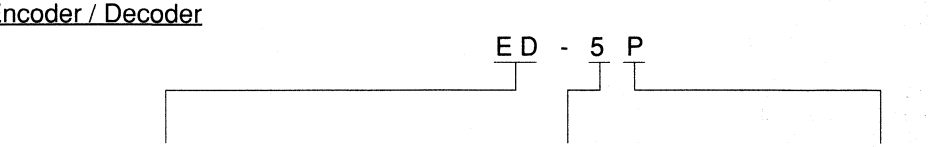
DMOS Proprietary Products



FAMILY TYPE	POLARITY	FAMILY NUMBER	BVDSS DIVIDED BY 10	PACKAGE TYPE
A = Lateral DMOS Arrays	N = N-Channel	01	02	N1 = TO-3
		03	04	N2 = TO-39
		05	06	N3 = TO-92
T = Low Threshold DMOS Discretes	P = P-Channel	06	09	N5 = TO-220
		07	10	N6 = 14-Pin Plastic DIP
		11	16	N7 = 14-Pin Ceramic DIP
V = Vertical DMOS Discretes & Quads	C = Complementary (N & 2P)	12	20	N8 = SOT - 89
		13	24	N9 = TO-52
		21	30	NA = 18-pin Plastic DIP
L = Lateral DMOS Discretes	Q = Arrays	22	32	NF = 20-Terminal Ceramic LCC
		25	35	WG = 20 Lead SOW
			40	ND = Die in Waffle Pack
			45	NW = Die in Wafer Form
			50	
			55	
			60	
			(e.g., 09 = 90V)	

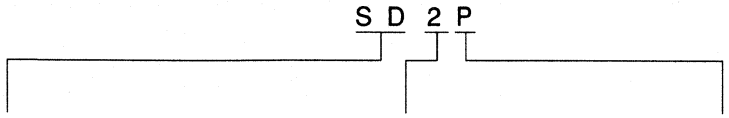
CMOS Products

Encoder / Decoder



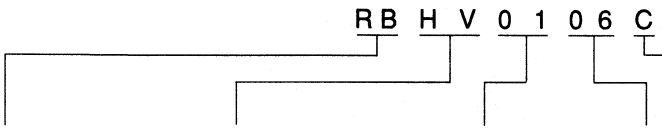
FAMILY TYPE	NUMBER OF ADDRESS BITS	PACKAGE TYPE
ED = Programmable Encoder/Decoder	ED-5 = 5	PJ = Molded Plastic Surface Mount J-Lead Chip Carrier
	DC-7 = 7	
	ED-9 = 9	P = Molded Plastic DIP
DC = Data Coder	ED-10 = 10	X = Dice
	ED-11 = 11	WG = Small Outline Surface Mount
ET = Encoder/Transmitter	ET-13 = 13	
	ED-15 = 15	
	ET-15 = 15	

Smoke Detectors



FAMILY TYPE	PRODUCT DESIGNATOR	PACKAGE TYPE
SD = Smoke Detectors	2	P = Molded Plastic DIP X = Dice

HVIC Products



HI-REL

RB = Hi-Rel 883 type processing

RC = Mil-Temp Testing only

FAMILY TYPE

HV = High Voltage IC

PRODUCT DESIGNATOR

03	56
04	57
04H	58
05	60
06	341
06H	343
09	345
10	348
12	500
14	501
15	518
16	61
18	67
21	6810
22	70
30	72
31	77
33	78
38	83
41	84
42	87
45	88
46	91
51	93
52	94
53	701
54	702
55	711
	712

ABSOLUTE MAX VOLTAGE DIVIDED BY 10

04	14	25
06	16	27
08	18	30
10	20	37
12	22	

(e.g., 22 = 220V)

PACKAGE TYPE

P = Plastic DIP
C = Ceramic Side Brazed
D = CERDIP
X = Dice
LC = LCC Ceramic
CS = Ceramic Chip Carrier-STD Bent Leads
DG = CERDIP Gullwing
PG = Plastic Gullwing
WG = SOW Gullwing
DJ = Quad CERDIP J Lead
PJ = Quad Plastic J Lead
T = 35mm TAB tape

Corporate Profile

Success Through Innovation

Supertex designs and manufactures complex proprietary and industry-standard integrated circuits (ICs). Our customers include the medical, data processing, military, telecommunications, instrumentation, and consumer product industries. Throughout the years the company has developed several advanced technologies utilizing high-performance Complementary Metal Oxide Semiconductors (CMOS) and Double-Diffused MOS (DMOS) processes.

In 1980, Supertex pioneered high voltage integrated circuitry with its proprietary HVCMOS® technology, a merging of the CMOS and DMOS process technologies onto one chip. Supertex HVCMOS chips have the "brains" and low power consumption of CMOS ICs and the high voltage output of DMOS FET transistors.

These advanced HVCMOS ICs, as well as Supertex's families of CMOS and DMOS products, provide performance and cost benefits, giving customers a competitive edge in developing their products.

Supertex now focuses on two process technologies, DMOS and HVCMOS, which allows for a diversified product mix of integrated circuits and MOS field effect transistors (FETs) and arrays. The Company's products are targeted for application-specific markets such as ultrasound imaging for medical electronics, flat-panel display terminals and high reliability products for military systems. Supertex has earned domestic as well as international recognition as a demonstrated technological leader in high voltage semiconductor products.

Product Development Milestones

Supertex has continued the commitment to product and technological development to enhance and complement our existing product lines. Supertex is a recognized world leader in high voltage ICs and MOSFET innovations. While responding to market demands for state-of-the-art products, the Company maintains a leadership position as an industry innovator, evidenced by the product development milestones listed below:

Introduced

1976 Industry leader in CMOS wafer foundry technology and production.

1977 Patent filed for silicon-gate High Power VMOS process.

First in the industry to introduce both N and P-Channel silicon-gate VMOS Power FETs.

1978 State-of-the-art High Voltage 500V Power VMOS FET introduced.

1979 Development of combined Bipolar and DMOS technologies (Superfet™).

High Voltage DMOS/CMOS IC technology developed for Medical Ultrasonic Imaging applications.

Widest product offering for CMOS Encoder/Decoder ICs, using Manchester coding.

1980 First in the industry to introduce High Voltage DMOS Lateral Arrays.

1981 First to develop fully TTL compatible CMOS Logic ICs.

1982 First fully integrated Electroluminescent (EL) Flat Panel Display Driver chip set, including gray scales.

1983 First to introduce 64-line density EL Display Driver ICs.

1984 First HVCMOS IC to be used in a major plotter program.

MVIC (40-volt) and HVIC technologies developed for wafer foundry production.

1985 First Hi-Rel HVCMOS display driver IC in the industry.

Introduction of industry's first low threshold N-Channel power MOSFET family.

1986 Introduction of low cost, low power 32-channel flat panel display driver ICs.

Introduction of industry's first low threshold P-Channel power MOSFET family.

First to introduce 8-Channel high voltage level translator chip.

1987 Introduction of 32-Channel complements (N and P-Channel) for high voltage, high current push-pull applications.

Introduction of low power 32-Channel AC plasma flat panel display driver ICs.

1988 Introduction of 32-Channel 300V complementary (N and P-Channel) high voltage ICs for electrostatic plotters and ATE bareboard testers.

Joint market introduction of microprocessor supervisory chips.

Introduction of first commercial gray-shade/video analog display driver ICs.

1989 Introduction of second generation low power high voltage analog multiplexers with CMOS control logic.

Introduction of single chip 225V push-pull IC with CMOS control logic.

Introduction of 64-Channel second generation 80V push-pull ICs with CMOS control logic and 400V open drain ICs.

1990 Implementation of macro-cell custom capability in high voltage ICs.

Introduction of ultralow threshold DMOS discrete transistors for Ni-Cad and other battery operated applications.

Custom Wafer Foundry

Supertex specializes in HVCMOS and DMOS Wafer Foundry production providing state-of-the-art wafer fabrication for Customer-Owned-Tooling (C.O.T.) production. Standard as well as modified processes can be produced per specific customer requirements. Engineering and preproduction volumes can be run with very short throughput times. Supertex can also support the customers' needs for back-end packaging and testing.

In addition, Supertex can also run standard metal-gate CMOS and PMOS processes.

DMOS FET Electrical Performance

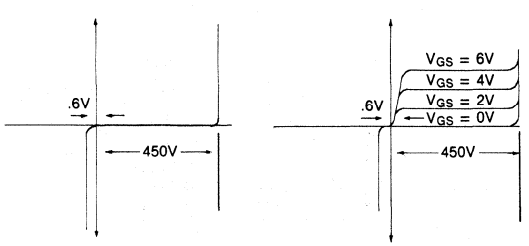
The electrical behavior of power MOS transistors has been explained by numerous authors. A different, and non-traditional way of viewing their behavior arises when the device structure is closely examined. The source and body regions comprise one side of a diode, with the drain region being the other side. A voltage on the gate allows carriers to flow from source to drain through an induced surface channel. Figure 1A shows the forward and reverse current vs. voltage characteristics of a diode, while Figure 1B shows the current vs. voltage characteristics of a power MOS transistor.

A power MOS transistor is characterized by a set of parameters different in many ways from a bipolar transistor. The parameters specified in a power MOS transistor data sheet are defined and briefly explained below:

A. $V_{GS(TH)}$ – The gate threshold voltage. It is defined as the voltage from gate to source required to produce a specified drain current. For ease of measuring, the drain is commonly shorted to the gate. (The measurement circuit is shown in Figure 2.)

Threshold voltage usually measured at a current in the range of 1 to 10mA. (Threshold voltage measurement can be normalized to the amount of source perimeter when comparing different size transistors. Full current is usually obtained at $V_{GS} = V_{GS(TH)} + 8$ volts (N-channel). The threshold voltage is a function of temperature as shown in Figure 3 for a 500 volt Supertex transistor. The decrease in the measured value of $V_{GS(TH)}$ is primarily caused by thermally generated carriers or leakage current that add to the induced surface current flow, thus decreasing the amount of applied voltage needed to obtain a specified current.

B. I_{GSS} – The gate to body leakage current. It is measured with drain and source at ground, and gate biased to specified voltage. NOTE: Due to input capacitance, large die size MOS transistors may prove difficult to measure with automatic test equipment, unless a preconditioning test is performed to charge the gate capacitance prior to test. (See Figure 4 for the measurement circuit.)



A. Diode characteristics

B. Gated diode characteristics

Figure 1.

This leakage current results from current flow through the insulating layer of silicon dioxide surrounding the gate. Typical DC-leakage currents are in the picoampere range between the temperatures of -55°C and +200° C. This value is well below the level of concern in most power conversion circuits. When an on-chip diode is incorporated between the gate and the source, the leakage current, which is that of a reverse-biased diode, doubles approximately every 10°C.

C. I_{DSS} – The zero gate voltage drain current or offstate leakage current. It is determined by applying specified voltage from drain to source (with gate shorted to source) and measuring the resulting current. (See Figure 5 for the measurement circuit.)

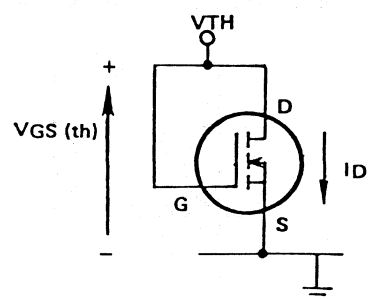


Figure 2. N-Channel $V_{GS(th)}$ Measurement

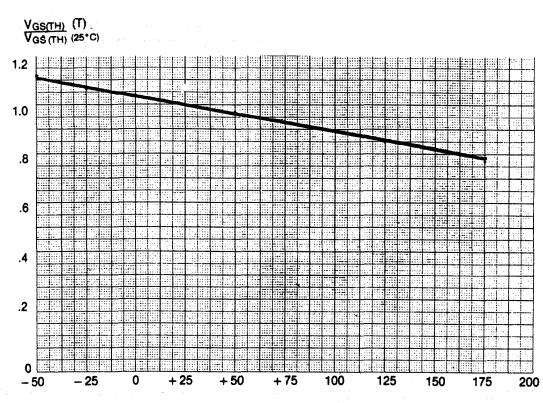


Figure 3. Normalized $V_{GS(th)}$ vs. Temperature for the VN03 Transistor

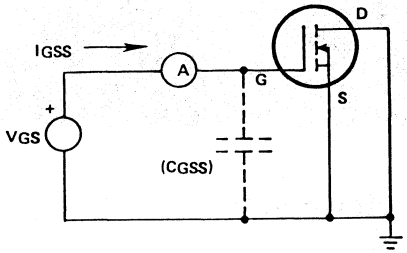


Figure 4. N-Channel I_{GSS} Measurement

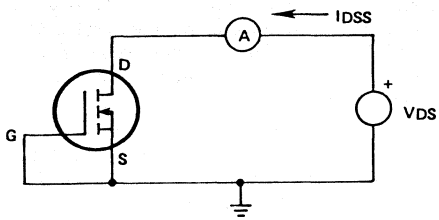


Figure 5. N-Channel I_{DSS} Measurement

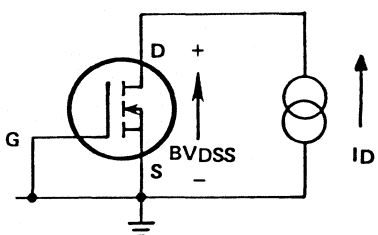


Figure 6. N-Channel BV_{DSS} Measurement

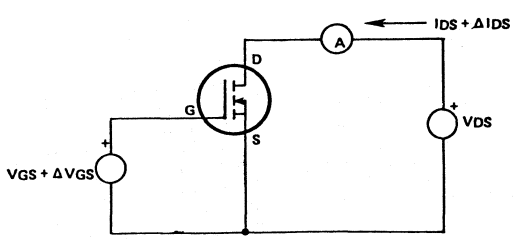


Figure 7. N-Channel G_{fs} Measurement

This leakage current is that of a reverse-biased diode. As with a reverse-biased diode, this current is a measure of the integrity of the structure and may degrade under extremes of voltage and temperature.

D. BV_{DSS} – The breakdown voltage of drain to source with gate shorted to source. It is determined by forcing a specified current from drain to source and measuring the resulting voltage. Properly designed DMOS transistors should not have a latchback breakdown and a low current measurement is sufficiently accurate. (See Figure 6 for the measurement circuit.)

This parameter is most likely to degrade if exceeded for an extended period of time in high voltage applications, because of the large current (and, hence, high power dissipation that may occur). A lower clamping breakdown voltage diode from source-to-drain will prevent degradation of the parameter.

E. g_{fs} or g_m – The small signal forward transconductance. It is the ratio of $\Delta I_D/\Delta V_{GS}$ measured for a 10% change in drain current at a specified quiescent drain bias point.

This parameter depends on device structure as shown in the equation below (see Figure 7 for measurement circuit):

$$g_m = \frac{\mu off\ Z \epsilon_{OX}}{Lt_{OX}} (V_{GS} - V_{GS(TH)})$$

where $\frac{Z}{L} = \frac{\text{Source perimeter}}{\text{Channel length}}$

μ_{off} = Effective carrier mobility

ϵ_{OX} = Gate Dielectric constant

t_{OX} = Gate oxide thickness

These parameters are shown in Figure 8. The forward transconductance is proportional to source perimeter, hence proportional to chip area. For a given device area, maximizing the source perimeter results in a maximum value of gm. This parameter is also increased by decreasing the gate dielectric thickness, but this approach limits the total voltage swing on the gate because of the dielectric strength of silicon dioxide (60V/1000Å of SiO_2). Typical gate oxide thicknesses are in the 1000Å range. In power MOS structures, the transconductance vs. V_{GS} varies as shown in Figure 9 for a 500 Volt VNO3 power MOSFET.

F. $R_{DS(ON)}$ – The static drain-source on-state resistance. It is measured as the drain-source voltage divided by the drain current at specified values of drain current and gate source voltage. (See Figure 10 for the measurement circuit.)

The on-state resistance of a high voltage MOS transistor is dominated by the resistance of the drain region. For a given breakdown voltage and device area, there is a minimum value of $R_{DS(ON)}$. The variations in source geometrics and body-to-drain breakdown structures discussed earlier are all aimed at realizing this minimum $R_{DS(ON)}$ value. In device operation, $R_{DS(ON)}$ may appear to be considerably higher than at room temperature. This behavior occurs because the heating of the device decreases the carrier mobility, thus reducing the current for a given voltage. This

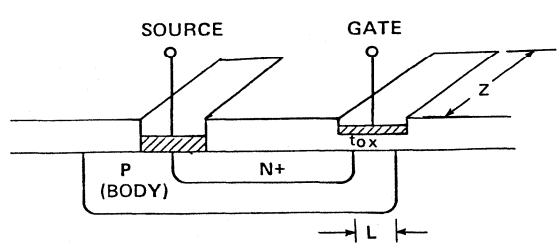


Figure 8. Parameters Affecting MOSFET Transconductance

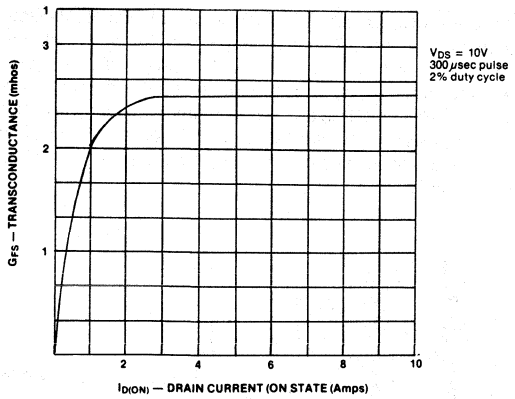


Figure 9A.

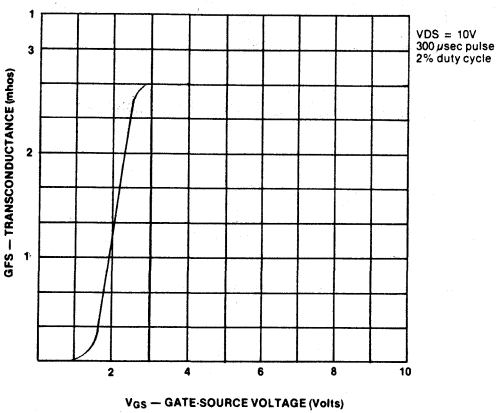


Figure 9B.

Figure 9. Transconductance vs. Drain Current or Gate-Source Voltage for the VN03

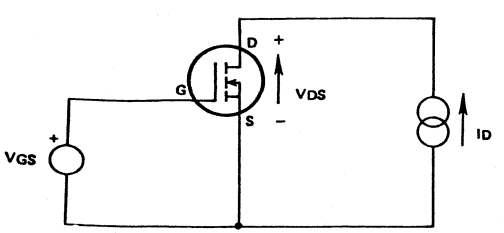


Figure 10. N-Channel $R_{DS(ON)}$ Measurement

behavior for a 500 volt VNO3 transistor is shown in Figure 11. This negative feedback characteristic is the key to power MOSFETs thermal stability.

G. $I_{D(ON)}$ – The on-state drain current. It is measured at specified values of drain-source and gate-source voltage. NOTE: To reduce heating of the device, this should be performed in a pulse mode, or with an adequate heat sink. (See Figure 12 for measurement circuit.)

The on-state drain current is proportional to the amount of source perimeter and the total chip area. Since current flow causes device heating, the pulsed value of $I_{D(ON)}$ is considerably greater than the steady state value because of the increasing value of $R_{DS(ON)}$ with temperature. This specific behavior is shown by the dotted line for the VNO3 in Figure 13.

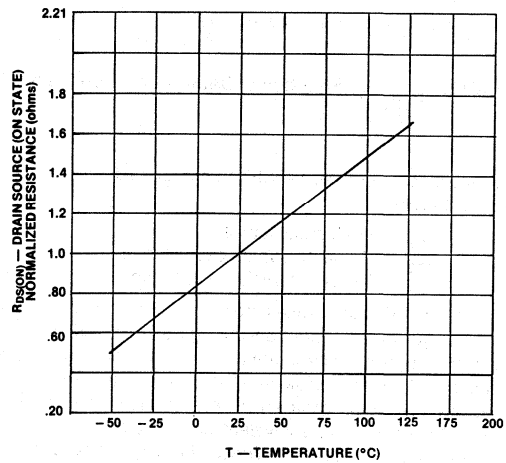


Figure 11. $R_{DS(ON)}$ as a Function of Temperature for the VN03

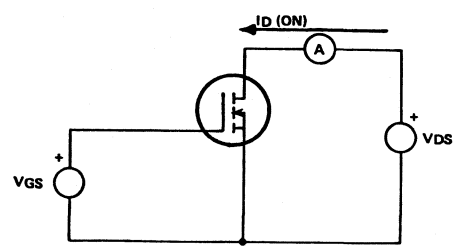


Figure 12. N-Channel $I_{D(ON)}$ Measurement

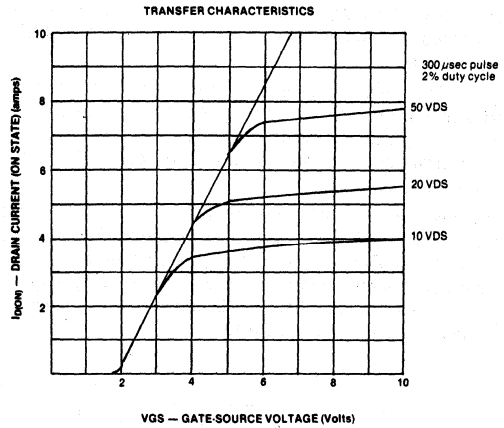


Figure 13. $I_{D(ON)}$ as a Function of Gate-Source Voltage for the VN03

H. Capacitances – Power MOSFETs are characterized by three capacitances:

1. C_{ISS}: Input capacitance
2. C_{OSS}: Common source capacitance
3. C_{RSS}: Reverse transfer capacitance

These measured capacitances are related to device structure as shown in Figure 14. We see from this figure that the value of C_{ISS} for a dual layer access structure will be correspondingly greater per unit area than an interdigitated structure. With these capacitances, a simple small signal equivalent circuit may be derived as shown in Figure 15. This equivalent circuit is also useful in more elaborate transient analysis. These three capacitances have been measured over temperature, with no appreciable temperature dependence found.

Conclusion

The power MOS transistor is a device with its own set of electrical parameters. These parameters depend on the device structure. The success with which power MOS transistors are used will depend on a designer's understanding of these electrical parameters and their limits. This article has attempted to link the performance of power MOS transistors to their optimum design and processing and to establish some physical limits for optimum performance.

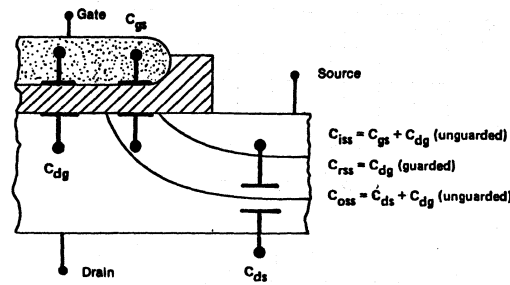


Figure 14. DMOS Transistor Capacitance

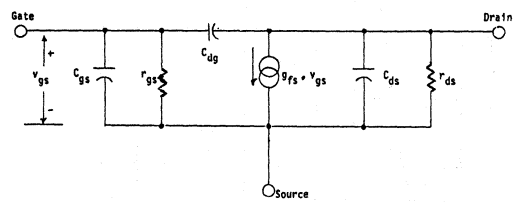


Figure 15. FET Equivalent Circuit—Small Signal

Low-Threshold MOSFETs: Structure, Performance and Applications

Since an increasing amount of attention is being focused on system interface from low-level logic, the need for higher current and/or low on-resistance at drive levels of only 3-5 volts has become a major concern. Supertex has always known of the importance of the gate drive consideration and has been offering N-channel low-threshold devices with threshold voltages of 2.4 and 1.6 volts for many years. Additionally, standard and low-threshold versions of P-channel DMOS devices are available. To understand the reasons that low-threshold processing requires very specialized techniques, one needs to understand the DMOS structure.

DMOS Structure

Most double-diffused MOS (DMOS) structures have very similar cross-section characteristics, as shown in Figure 1. For conduction to occur, a channel of electrons is needed between the gate and the source. This potential produces an inversion layer called the channel. The depth of this layer is the limiting factor in allowing current flow between the drain and source terminal. The greater the voltage applied, the deeper the induced channel; resulting in more current flow. The voltage needed to invert the channel region is called the threshold voltage $V_{GS(th)}$. However, when examining most manufacturers data books, one finds $V_{GS(th)}$ defined as the voltage needed to produce a specified drain current (I_D). This differs from the theoretical definition of knowing when a channel is produced, which is of little interest to power MOSFET users. Comparing $V_{GS(th)}$ at the same I_D simplifies the analysis of databook parameteric guarantees, allowing the designer to compare the product to actual needs.

The control of the threshold voltage is dependent on many factors, such as dopant concentration, gate-to-silicon work function and surface change. The greater the body dopant concentration, the larger the applied voltage needed to produce a channel, which translates to a higher threshold voltage. One method of reducing threshold voltage is to reduce the body dopant concentration until the required $V_{GS(th)}$ is met. This technique by itself is dangerous because it degrades other device parameters. The first and most important of these is drain-source breakdown (B_{VDSS}), which is a result of certain conditions, most commonly punch-through. Punch-through is defined as the drain voltage needed to create an electric field connecting the drain and source, as shown in Figure 2, at voltages less than the actual B_{VDSS} rating.

The susceptibility to punch-through increases dramatically as the body dopant concentration is lowered. There is an optimum body dopant level that is needed in order to stay away from the punch-through mechanism, but this concentration is too high for low thresholds. This is one of the reasons why P-channel devices typically have higher thresholds, because the optimum body dosage is higher than N-channel FETs.

Another technique, used by some manufacturers, is to lower threshold by reducing the gate oxide thickness. Again, there are tradeoffs using this method: (1) The input capacitance increases which will effect the switching speed efficiency and (2) the maximum gate voltage rating is decreased, making it more susceptible to input voltage spikes.

Supertex has developed a proprietary technique to successfully lower threshold voltage without these major tradeoffs. This method mainly depends on modifying the diffusion profile and altering the charge distribution to produce low-threshold N- and P-channel devices. This process, which makes use of Supertex's interdigitated design structure, allows typical thresholds of 1.1 volts for N-channel and 1.8 volts for P-channel, DMOS devices.

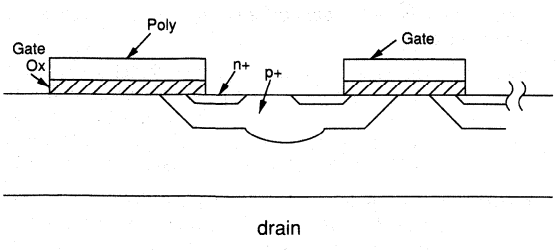


Figure 1. Double Diffused MOS (DMOS)

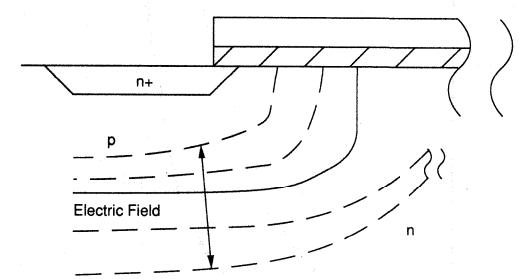


Figure 2. Electric Field Connecting Drain and Source

Part Number	IRF 520			VN12105			
Parameter	**Min**	**Max**	**Conditions**	**Min**	**Max**	**Conditions**	**Unit**
$V_{GS(th)}$ Gate Threshold Voltage	2.0	4.0	$V_{DS} = V_{GS}$, $I_D = 250\mu A$	0.8	2.4	$V_{DS} = V_{GS}$, $I_D = 10mA$	V
$ID_{(ON)}$ On-State Drain Current	8.0		$V_{DS} > I_{D(ON)} \times R_{DS(ON)}$ max $V_{GS} = 10V$	20.0		$V_{DS} = 25V$ $V_{GS} = 10V$	A
				5.0		$V_{DS} = 25V$ $V_{GS} = 5V$	A
$R_{DS(ON)}$ State Drain-to-Source On Resistance		0.3	$V_{GS} = 10V$ $I_D = 4.0A$		0.3	$V_{GS} = 10V$ $I_D = 10.0A$	Ω
					0.45	$V_{GS} = 5V$ $I_D = 2.0A$	Ω

Table 1. Comparison between power MOSFET and standard threshold Supertex device

An added benefit of Supertex's design is the lower input capacitance achieved by the interdigitated geometry, rather than the more conventional closed cell approach. "The Ideal Interface," an article published in Supertex's DMOS applications booklet, discusses these geometric considerations. As stated in the article, less charge is needed to control the device input. Therefore, it can be concluded that a lower threshold device will start conducting earlier for a given gate drive and allow control of larger drain current than a higher threshold device.

The availability of such low-threshold DMOS devices insures the performance needed to be driven by low level logic systems, in which the maximum voltage available is only 3-5 volts.

Performance Advantages

With the first device shipped in 1982, Supertex was the pioneer in low-threshold DMOSFET technology and still maintains a performance edge over other manufacturers. Supertex currently supplies the lowest threshold power MOSFETS in the industry. A threshold voltage of 1.6 volts for N-channel and 2.4 volts maximum for P-channel clearly supports this claim.

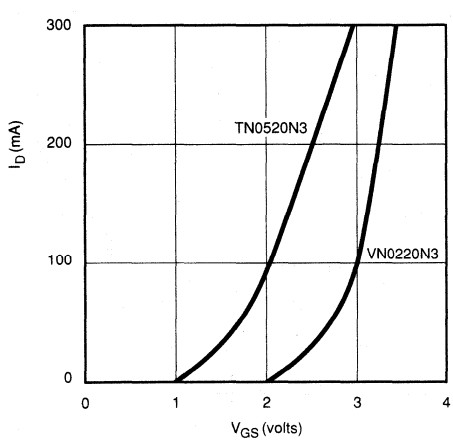


Figure 3. Typical Transfer Characteristics

Supertex measures threshold voltages at I_D = 1mA, 2.5mA, and 10mA for small, medium and large-sized devices, respectively. Although some manufacturers use test conditions as low as I_D = 250μA for large devices, Supertex devices, in comparison, still have lower values of threshold voltages at higher values of I_D. See Table 1 for a comparison between a popular power MOSFET and a standard-threshold Supertex device.

A true comparison can be made by normalizing the value of the I_D test condition. The threshold voltage for VN1210N5 will be lower than 2.4 volts, maximum, when it is tested at I_D = 250μA. Supertex's test conditions therefore portray a realistic picture of the device's capabilities at low V_{GS} conditions.

The threshold voltage is an important indicator of performance at low V_{GS} conditions because a device that starts conducting at a very low bias will exhibit good characteristics under such conditions. In fact, $R_{DS(ON)}$, maximum, and $I_{D(ON)}$, minimum, at low V_{GS} conditions are much more important than just the threshold voltage value because quiescent gate voltage conditions are usually at least a few volts above the $V_{GS(th)}$ value. Figure 3 shows the transfer characteristics of a standard-threshold and a low-threshold device. For example, if the drain current requirement is 100mA, TN0520N3 will typically need V_{GS} = 1.8 volts and VN0220N3 will require 2.8 volts to achieve this value. In case a 2.8 volts drive is not available, as in many applications, a VN0220N3 will be incapable of functioning in the circuit. In spite of the TN05 die being half the size of a VN02, the TN0520N3 performance is far superior at low gate to source voltages.

When confronted by low gate drive voltage, a designer basically has two choices:

Approach 1: Use a large industry-standard-threshold device to obtain the required low $R_{DS(ON)}$, maximum, and $I_{D(ON)}$, minimum, values. $I_{D(ON)}$ can be obtained from the transfer characteristics and $R_{DS(ON)}$ values will be read off the typical saturation or output characteristics.

Approach 2: Compared to the device used in Approach 1, use a relatively small (die size), low-threshold device to achieve the desired $I_{D(ON)}$ and $R_{DS(ON)}$ at the given minimum gate-to-source voltage.

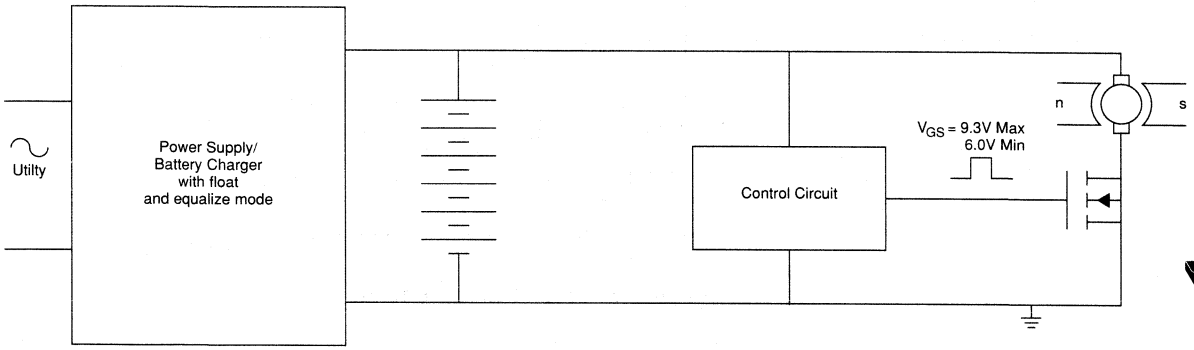


Figure 4. Motor of a Fluid Injection Pump

Comparison of Approach 1 and 2

1. Large die always have larger parasitic capacitance and consequently slower switching speeds. This could pose a restriction in many applications, where limited gate drive charging current is available.
2. Large die must be accommodated in large packages, and this may result in unnecessary waste of board space. For example, the total volume occupied by a TO-220 package including stand off could be 8 to 10 times more than a TO-92 package.
3. A judicious choice using smaller die in a smaller package can result in considerable cost savings. Compared to a large die with more silicon and several times the raw material content for packaging, a low-threshold TO-92 will definitely be a much more cost-effective alternative.

Supertex publishes $R_{DS(ON)}$, maximum, and $I_{D(ON)}$ minimum, specifications at V_{GS} = 5 volts (see Table 1). This data is very useful to a designer because it is always desirable to rely on guaranteed values instead of typical curves. Typical curves are based on a high statistical probability of the majority of devices closely meeting values on the curves. They do not 100% guarantee performance of all devices. Manufacturing tolerances and some variations from one fabrication lot to another are likely to cause lower than expected values of these parameters. Depending entirely on curves tends to be risky for production runs even if prototypes built earlier perform satisfactorily.

The combined effect of low-threshold voltage and low-input capacitance is ease of drive, which is a key consideration in most circuits employing power MOSFETs. What better trait can a designer expect than a small amount of charge controlling high voltages and large currents? These low-threshold FETs from Supertex are ideally suited to interface low-voltage logic to the outside world.

Applications

Low-threshold power MOSFETs play a key role in circuit design whenever there is a low gate-to-source voltage situation. Conventional devices are often very inefficient and sometimes unusable in some applications as follows:

- Handheld, battery-operated equipment requiring satisfactory operation at low/end-of-discharge voltages. This is necessary for complete utilization of battery energy. Inadequate turn-on of a FET can cause two problems: A) loss of control signal or data; or B) loss of power due to resistive losses. Supertex TN/TP series devices are being used for a variety of data acquisition and remote-control applications.
- Medical equipment with battery back up is another popular application. Figure 4 shows the motor of a fluid injection pump powered by the utility supply and backed by a NiCad battery. The V_{GS} = 6 volts condition demands careful attention, because the $R_{DS(ON)}$ has to be low in order to ensure a low drain to source voltage drop. A large voltage drop can A) affect motor performance, and B) cause high I^2R losses, reducing system efficiency and battery back-up time.

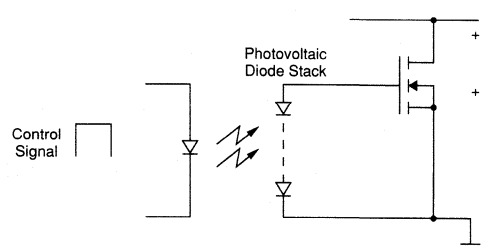


Figure 5. Photovoltaic Drive Scheme

- Solid-state relays utilize optically-isolated drive schemes for isolation purposes. Figure 5 shows a commonly-used photovoltaic drive scheme. Usually a low voltage is available to turn on the FET to meet the relay's assured $R_{DS(ON)}$ specifications. Precautions are taken to avoid excessive drive since the charge applied during turn-on must be quickly discharged during turn-off. Turn-off circuitry is not shown in this simplified schematic.
- Figure 6 shows a simple charge pump converting 5vdc to 12vdc. The key parameter for efficient functioning of this circuit is $R_{DS(ON)}$ at V_{GS} = 5 volts.

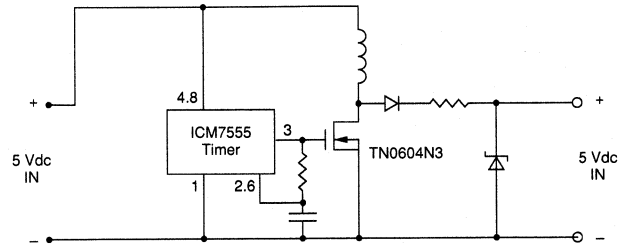


Figure 6. Charge Pump Converting 5vdc to 12vdc

- Telephone handsets encounter wide variations of voltage during normal operation (Figure 7). While the DC voltage appearing across the unit may vary from approximately 3 to 25 volts when the phone is off the hook, high voltage AC ringer signals and associated transients have to be handled safely. Moreover, atmospheric disturbances (e.g., lightening and RF radiations) are picked up by the lines, inducing high voltages which are suppressed by MOVs, gas discharge tubes, etc. (not shown in the figure).

Supertex low-threshold TN05 devices used for the pulser and mute switch operate satisfactorily, even at voltages as low as 3 volts. A TN0524N3's guaranteed $I_{D(ON)}$ minimum = 100mA at V_{GS} = 3 volts is more than adequate for this purpose.

Advances in low-threshold power MOSFET technology offers several useful choices to a designer. Circuit design for many applications are simplified and use of components minimized. Consequently, system complexity is reduced and reliability enhanced. All these benefits combined with the cost-effectiveness of the devices makes the low-threshold FETs an excellent choice.

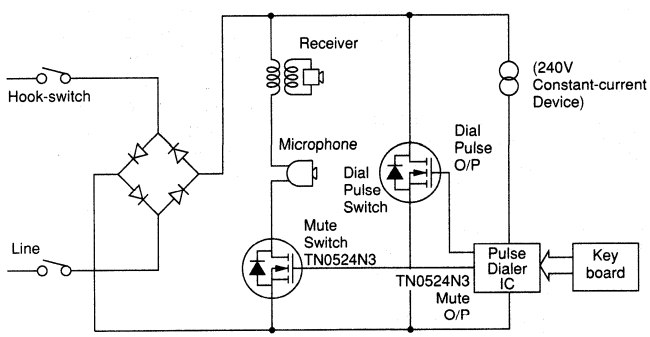


Figure 7. MOSFETs in a Telephone Handset

Basics of EL Panel Drive Techniques

Thin film electroluminescent (EL) panels operate on a principle of successive pulses of opposite polarity. These pulses must exceed a threshold of approximately 200V for the panel to emit light.

A flat panel display is a sandwich of phosphor material with dielectric coating on either side; transparent ITO (indium Tin Oxide) row electrodes on one side and column electrodes on the opposite side. These layers are built up on a sheet of glass to form a very thin, lightweight display panel.

Since the drive electrodes are dielectrically isolated from the phosphor material, and each other, the display panel exhibits a capacitive load to the drive electronics. On larger panels this capacitance can be quite high. Surge currents can be large, therefore coupling from the row to the column electrodes should be considered.

The drive electronics used to operate the panel are organized in a manner to surround the display panel with contacts as shown in Figure 1.

Generally, the row electrode electronics supply the major portion of the threshold voltage, called the scan pulse, and the opposite polarity "refresh" pulse , which is necessary for the panel to emit light. The refresh pulse is usually applied to all rows at one time while the scan pulse is applied to one row at a time (starting with row #1), similar to a television raster scan.

Depending on the data to be displayed in each column, the column electrode electronics supply a voltage of opposite polarity to the row scan pulse. This combination of row and column voltage across the phosphor will exceed the threshold and cause the phosphor in areas between the energized row electrodes and the energized column electrodes to glow. This sequence, applied to successive rows, causes certain portions of the display to be illuminated.

Because the phosphor requires successive pulses of opposite polarity to operate, an opposite polarity refresh pulse is applied to all row electrodes simultaneously while the column drivers are kept at ground. The sequence then begins again at row #1 with the next frame of data. Figure 2 is a representative timing diagram of the signals applied to a TFEL panel showing the first four rows and the first column.

Due to the fact that the phosphor illumination threshold has a slope of illumination versus applied voltage within a short range, the column drive electronics can be made to vary the applied voltage within this range, dictated by the intensity of light desired for a particular element on the display. By this means, a grey shade image can be created using the EL display.

Row Drivers (HV03, HV05)

To allow the open drain outputs to provide the opposite polarity pulses to the panel, the sources of the output MOSFETs must be switched between the different voltages required for the panel.

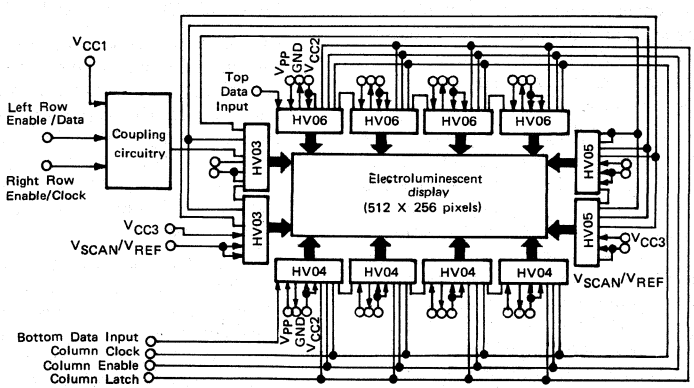


Figure 1. Block diagram of the driver system for a TFEL (Thin Film Electroluminescent) panel. Note that the column drivers have two data lines with interleaved pixel data.

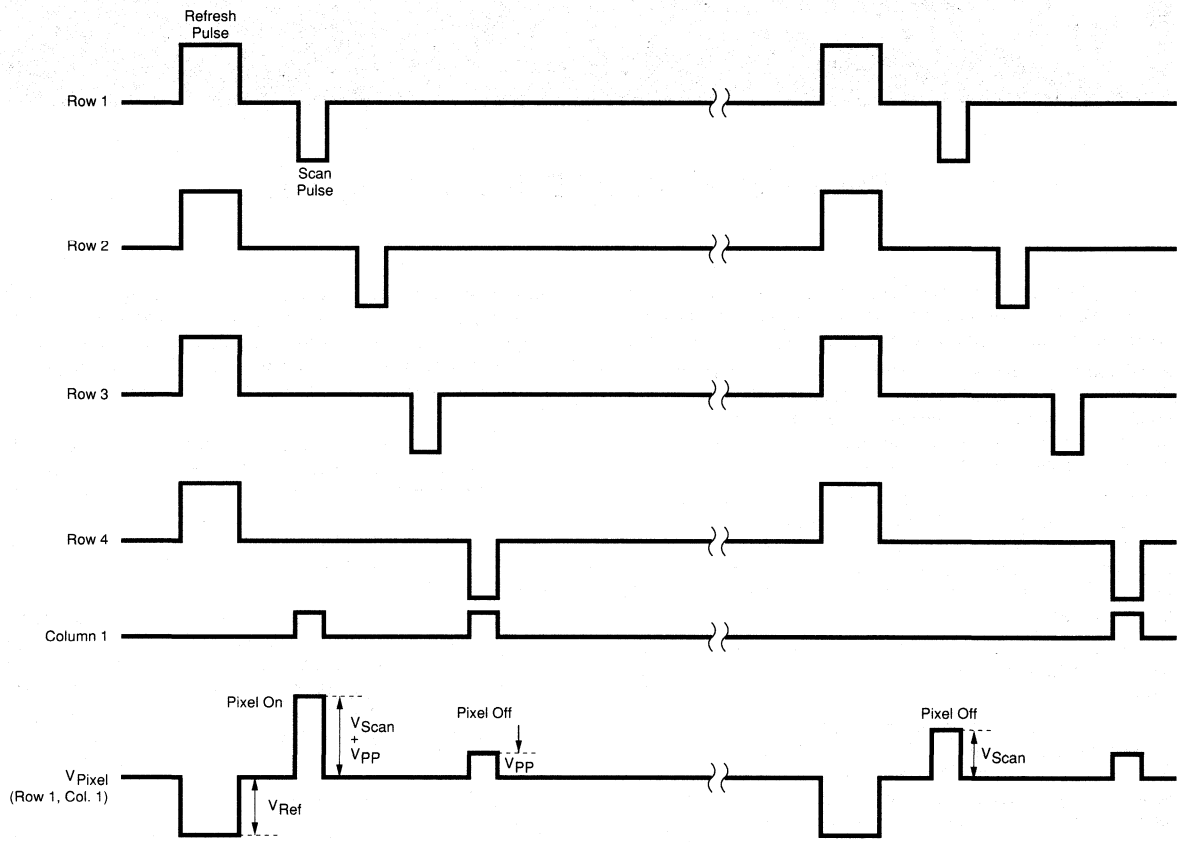


Figure 2. Simplified diagram illustrating row and column timing to operate an EL Panel. V_{REF} only lights pixels that were turned on by V_{SCAN} and V_{PP} pulses in the previous frame of information.

Since these MOSFET source connections are connected to chip ground, the entire device needs to be isolated or "floated" from the system ground. The control signals to the row driver chips therefore must be opto-isolated from the system ground. Figure 3 shows a simplified way to accomplish this.

The two high voltage supplies are switched to the row substrate (driver chip ground) using MOSFET switches. Application of the voltages to the panel is as follows: the refresh pulse is applied to the entire panel at the same time by pulsing on "C," forward biasing the body-drain diodes on all row outputs. The panel is returned to ground by pulsing "D" while having all the row driver outputs on. The scan pulse is applied, one row at a time, by pulsing on "A" while the selected row output is on. The selected row is returned to ground by turning on "B." The next row to be scanned is then selected, and the scan is repeated; first "A," then "B." When the entire panel has been scanned, the refresh sequence is executed; first "C," then "D." The scan cycle then begins again. In this way the proper voltages and sequences are applied to the panel for operation.

Monolevel Column Driver (HV04, HV06)

The column drivers are used to apply the data to be displayed onto the panel. The data for each row of picture elements (pixels) is loaded into all the column drivers serially and latched into the output latches. The outputs are thus turned to their desired state, and then the high voltage (V_{PP}) is applied. Columns selected for data display are connected to V_{PP} through the CMOS output and are pulled up to V_{PP}. The combination of the column V_{PP} and the selected row voltage will cause selected pixels to light in that particular row.

During the time that the data for one row is being displayed, the data for the next row is being loaded into the shift registers, awaiting the display of the next row. When a row is completed, the column driver V_{PP} is brought low and the data waiting in the shift register is loaded into the output latches. The cycle then begins again for each successive row.

The column drivers are designed with a serial shift register output for use in cascading the column drivers together. This allows the data for one row to be loaded serially, using one serial input at the first column driver device.

Gray Scale Column Driver (HV38)

This device is designed to take four data inputs in parallel into four shift registers. The data is then taken from equivalent stages of each shift register and converted to an analog level, 1 of 16 between ground and V_{PP}. this is done by a digital counter using four bits of input data. The counter is preset with data counting down to turn off a transistor. This transistor isolates a ramp input (VR) from an internal storage capacitor, which controls a CMOS output stage. The output voltage therefore represents the value of the ramp voltage (VR) at the time the counter for each output counted down. This voltage, applied to the column of the panel, combines with the row scan voltage to vary the light output from each pixel in the selected row.

Panel Brightness

The varying brightness of an EL panel by voltage variation can only achieve a limited range. Dramatically increased panel output, such as required by panels to be operated in direct sunlight, requires another method of increasing output. This is done by increasing the panel frame rate, or refresh rate. Normal CRT based systems work on a 60Hz frame rate. Most applications of EL panels replacing CRTs, then, also operate at this rate. This is fine for office and home use but does not provide enough brightness to accommodate most military applications. By increasing the refresh rate up to tenfold, a dramatic increase in brightness can be achieved.

This increase in refresh rate requires some changes in the column driver configuration. Instead of cascading all the column drivers together, each column driver shift register input is driven in parallel by the controlling system at the same time. This increases the number of data lines required but allows the data to be loaded much faster, enabling the faster frame rates desired. The row drivers are used at a much slower rate, so no changes are required to achieve faster operation.

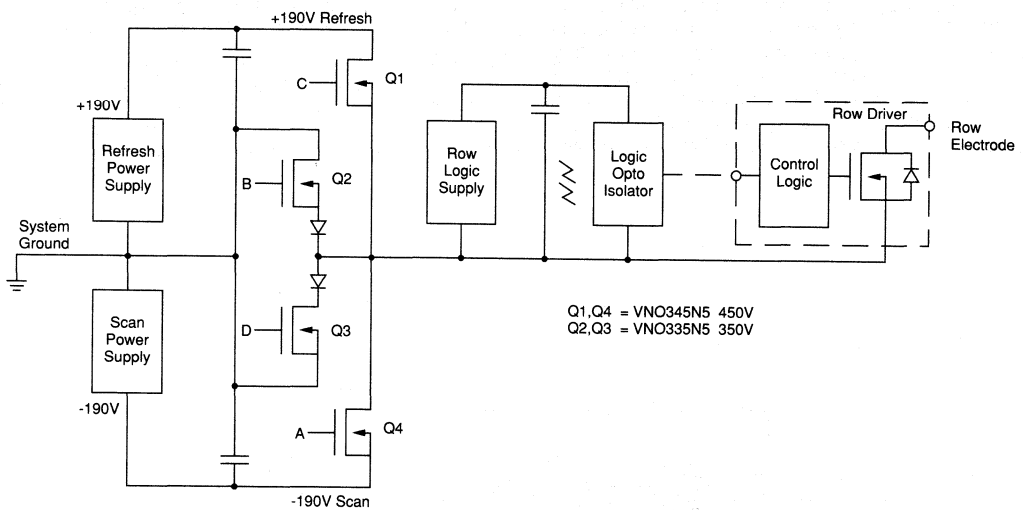


Figure 3. Row driver panel switching block diagram.

Cascading Encoder-Decoder

The Supertex family of Encoder-Decoder devices allows address matching of up to 32,768 different codes. Four bits of data can be sent to up to 2048 different receive devices. This has been adequate for the vast majority of applications. Some applications, however, require even more addressing capability than the largest part can offer.

A cable TV control system, with which a cable company would want to control operation of all the decoders in their area, is one application in which the possible remote addresses could number more than 32,768. Another possible use is remote meter reading of domestic and industrial power meters by the local utility company. This offers tremendous savings in labor costs over manual meter reading. Both of these applications require a low cost, simple means of implementing single unit identity coding of a large number of remote devices. The Supertex ED devices offer this capability.

Mode of Operation

Figure 1 shows a simple means of cascading two ED devices to allow more than 1.07×10^9 addresses. The basic requirement for using this design is that the transmission into the receiver consists of two ED-style data packets (preamble and data) separated by a short interval. The first data packet will go to the primary ED device (ED #1) and the second data packet will go to the secondary ED device (ED #2). These groups of two data packets must be separated by a much longer delay. Figure 2 is a timing diagram of the operation of this cascaded receiver.

On initial condition, in which the receiver is waiting for an address group to arrive, one-shot IC #1 enables the incoming signal into the Start/Data Input (SDI) of ED #1 while disabling the path to ED #2. When the group arrives, the first data packet is input into ED #1. When this data packet, both preamble and data, have been

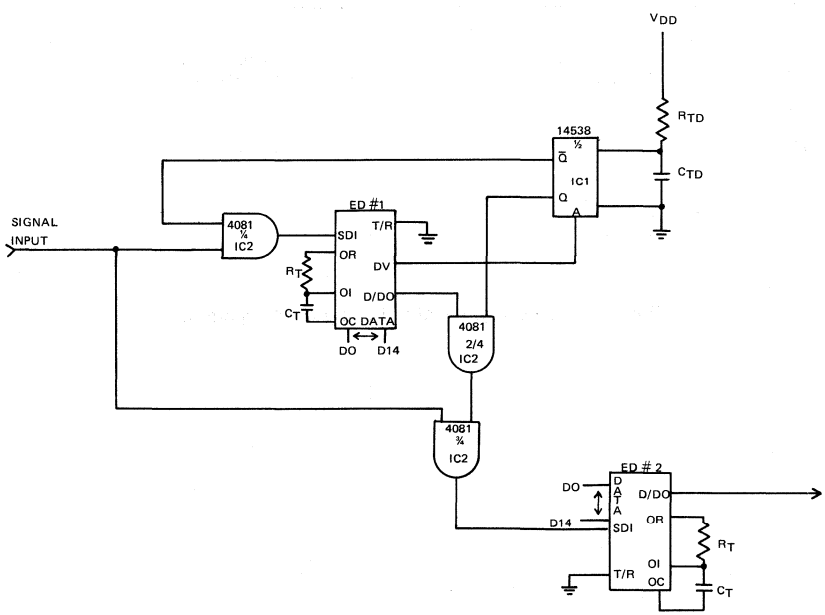


Figure 1.

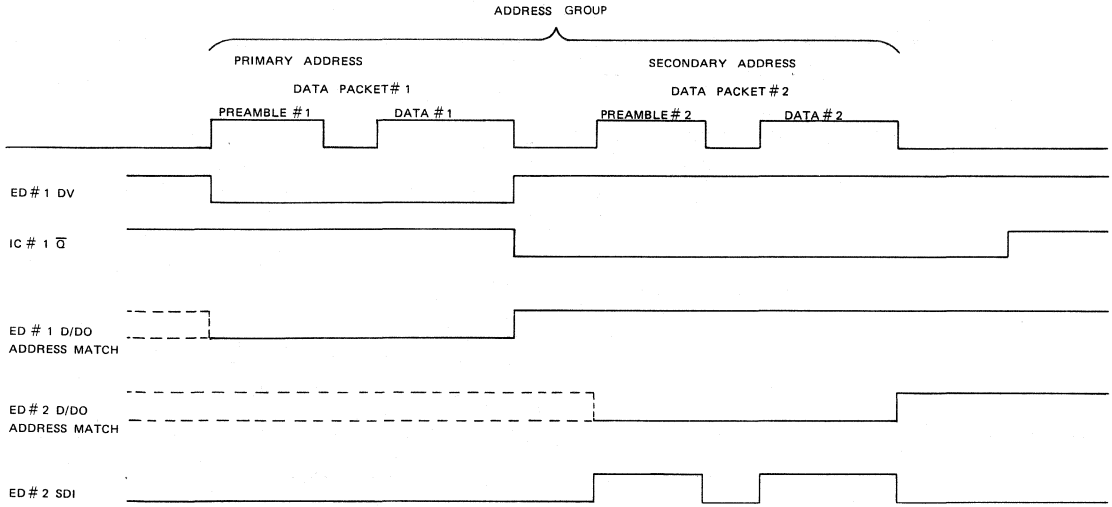


Figure 2.

received by ED #1, the Data Valid (DV) signal will go high, triggering the one-shot. This will disable the SDI input to ED #1. If the data in data packet 1 matched the address data on the ED #1 data pins, then ED #1 Decode/Data Output (DDO) pin will also go high. This and the triggered one-shot enables the path from the signal input to the SDI pin of ED #2. The second data packet will then be received by ED #2 and compared to the data input pins. If the address matches, the ED #2 DDO will go high.

The one-shot timing must be set to allow data packet 2 to be completely received before the one-shot times out and returns to the off condition. This time period will vary depending on the transmission speed of the communication link and the ED speed used. After both data packets have been received and the one-shot has timed out on all the receivers in the system, the transmitter can then send out a new address group.

Address Decode

The circuit shown in Figure 1 and described in the previous section implements the address decode function. The DDO pin on ED #2 should be connected to a device that operates on a positive going edge to signal the correct addressing of both ED #1 and ED #2.

Different combinations of ED devices can give a different number of possible addresses. The following table illustrates these possibilities:

ED #1	ED #2	# of possible addresses
ED-15	ED-15	1,073,741,824
ED-15	ED-9	16,777,220
ED-15	ED-5	1,048,576

The ED-9 cannot be used in the ED #1 position because it does not have a DV output available.

Address and Data

Often it is necessary not only to address a particular device within a large number of devices in a system, but also to send some amount of data only to that device. The ED-11 and DC-7 devices easily implement this capability in the cascaded design. Figure 3 illustrates a data transmission variation of the cascade circuit.

The input controls for ED #1 and #2 operate the same as for the address matching case. In this case, however, the Serial Data Output (SDO) and Data Clock (DC) of ED #2 are connected to a 4094 serial to parallel shift register. The SDO is connected to the Data In pin, while the DC is connected to the Clock pin to clock the data into the shift register. The rising edge of the ED #2 DDO signal is converted to a pulse and used to transfer the data from the shift register to the parallel output latches of the 4094 if the address match is detected. The DDO pulse is also available from the receiver system as an interrupt to the external circuitry signalling the arrival of data from the transmitter.

ED #1	ED #2	Data Bits	Address Combinations
ED-15	ED-11	4	67,108,864
ED-15	DC-7	8	4,194,304
ED-15	ED-5	15	32,768 *special case
ED-5	ED-11	4	65,536
ED-5	DC-7	8	4,098
ED-5	ED-5	15	32 *special case

* The special cases noted above represent a situation in which 15 data bits must be received. This is implemented by using ED #1 only for address matching and using ED #2 only for data reception. To receive 15 bits, two 4094s must be serially connected to form a 16 bit shift register. The Data Valid (DV) output of ED #2 would be connected in place of the DDO output to strobe the data into the latches of the 4094s.

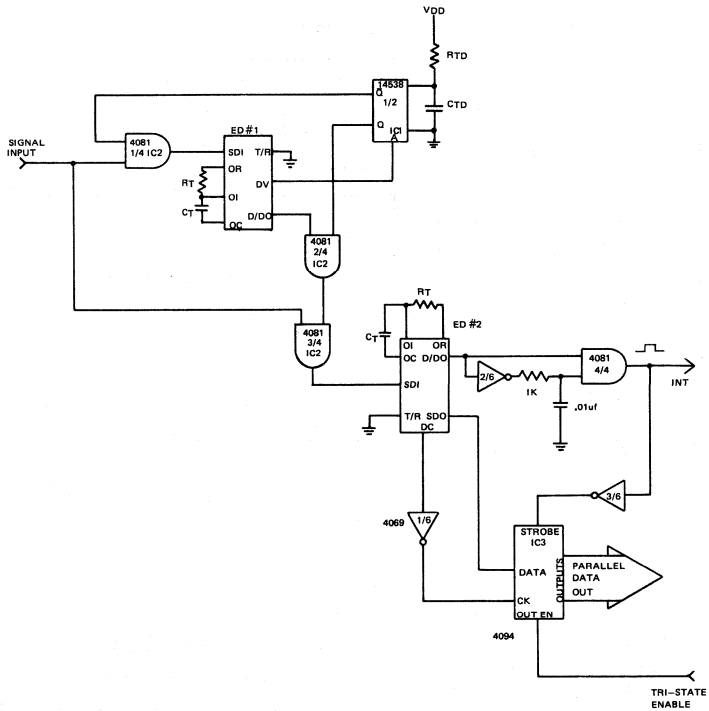


Figure 3.

Transmitter

The transmitter used to address this receiver design would normally be microprocessor controlled, with a peripheral adapter port connected to the data pins of an ED-15 device. The data pins could be changed to implement the data packet #1 and #2 by the much faster microprocessor. Alternatively, two ED-15s could be OR-gated to a transmission media and controlled by normal logic.

Conclusion

This application should help implement a simple low cost means to address a large number of remote devices in an addressing system. If there are any questions or suggestions for improvement, please contact the applications engineering department at Supertex.

DC-7, ED-5, ED-9, ED-11 Applications

The Supertex "ED Family" of remote control encoder/decoder chips has almost unlimited uses. To make the user aware of some of the salient features of these unique ICs, we have put together this application note. When used in conjunction with the data sheet for these parts, most of the questions that may arise from attempts to design systems around them may be answered.

Remote Control Systems

As electronic systems become increasingly more sophisticated, the need to perform certain functions at a distance becomes increasingly important. In many cases, the need arises for central automatic control of remote operations. Here, too, remote control devices are necessary. Until recently, remote control of various functions required a plethora of discrete circuits, raising the cost, in many cases, to prohibitive levels. Recently the MOS LSI industry has responded with integrated circuits of varying usefulness and complexity. Most of these ICs are geared to perform a single task such as opening garage doors, controlling TV functions, and the like. Until now, all remote control ICs were sold in a set; i.e., a separate encoder and decoder. The Supertex EDs on the other hand are a single chip. The encode/ decode function is determined by a programming pin, which is tied to V_{DD} for the encode function and V_{SS} for the decode function. Having only one chip reduces the complexity of purchasing remote control. Spares are easier to stock, and reliability is enhanced.

The Supertex EDs

In addition to the "lock-and-key" feature of ED codability, the ED-11 has the feature of being able to transmit and receive 4 additional bits of binary data which are available at the decoder's output. The DC-7 has 8 bits of data. These can be used to perform tasks such as channel recognition (with digital readouts), microprocessor interface and event sequencing. This feature makes the ED family of encoders/decoders extremely versatile.

Simple, Two-Wire Interface Utilizing ED-15s

The basic application for the ED-15 is the simple two wire interface. This configuration is useful for optimizing ED parameters such as encoder/decoder frequency stability, and lockup time. It is also a useful way of observing waveforms and can be invaluable for troubleshooting a more complicated system using other transmission media.

In Figure 1, the output is not latched and will stay high only so long as the trigger circuit keeps cycling the encoder. The CMOS oscillator is necessary to produce the start pulse. By utilizing an oscillator, it is possible to get a continuous data stream. This is useful for observing all waveforms involved. The start pulse oscillator can even be used to trigger the scope, making the waveforms easy to sync. The wire used can be just a jumper when

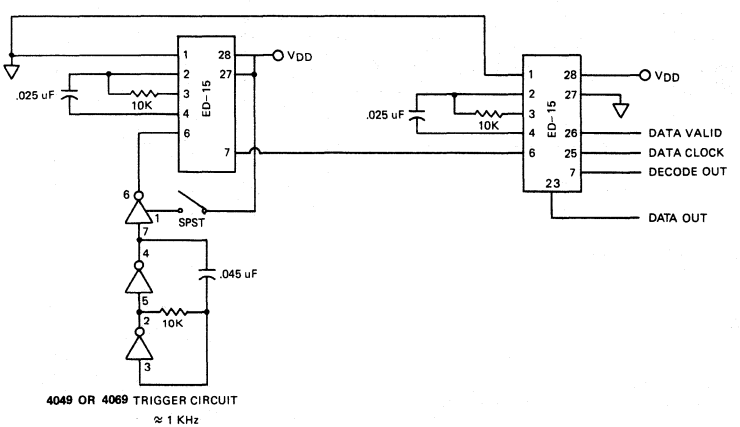


Figure 1. Basic Two-Wire ED System

both encoder and decoder are on the same breadboard, but twisted pair or shielded cable should be used for long runs.

ED-11, DC-7 System Utilizing Hardwire Transmission and Output Latches for Additional Data

As stated earlier, one of the great features of the ED family of encoder/decoders is the ability of the ED-11 and ED-5 to transmit 4 bits of binary code along with the "lock-and-key" recognition bits, the DC-7 to transmit 8 bits of binary code along with the "lock-and-key" recognition bits, and these 4 or 8 bits to appear at the data clock output of the receiver. This feature allows the transmission of useful data instead of just the "code valid" output common to other so-called remote control encoder/decoders. The following is an adaptation of the hard-wired system seen above. The difference is that even though an ED-15 is used for the encoder, an ED-11 is used for the receiver, and this data is decoded for use as a parallel latched data bus. Of course, since the last 4 bits in the ED-11 are used as actual transmitted non-dedicated data, it has only 2048 different possible code combinations instead of the 32,768 combinations possible with the ED-15 system. The trigger circuit is the same as above and will be represented from here on only as a block diagram.

In Figure 2, an ED-11 can be used for the transmitter as well as for the receiver. An ED-15 is shown to illustrate the compatibility of the ED family of encoder/decoders. The 4015 in the circuit is a serial to parallel converter and the 4042 is a quad 4-bit latch. The data valid pin is used to clock the parallel data into the latch and Q as well as $\overline{Q}$ outputs are available on this IC. The bit sequence chart is given below the schematic to show the relationship of the "key-code" bits to the last 4 data bits.

In Figure 3, a DC-7 can be used for the transmitters as well as for the receiver. An ED-15 is shown to illustrate the compatibility of the ED family of encoder/decoders. The 4094 in the circuit is a serial to parallel converter and an 8-bit latch. This circuit demonstrates the use of the DC-7 in which both the data and address can be transmitted from one location to another and both the data and address of the transmitter recovered. In an application in which only the data is to be recovered and a special address assigned to the receiver, the D/DO signal should be connected to the 4094 and only the TOP 4094 used. In a system in which all incoming data and addresses are to be decoded the DV signal would be connected to both 4094s as shown. The bit sequence chart is given below the schematic to show the relationship of the "key-code" bits to the last 8 data bits.

Infrared Transmission

Often it is necessary to transmit data over some distance without wires. In such an instance it is necessary to couple the data (in this case from ED-series encoder/decoders) by way of some transmission media. Here is a simple but effective way to use IR as a medium for signalling between two EDs.

The circuit in Figure 4 is designed so that the ED-15 is operating at 25KHz. The output of the chip (Pin 7) is applied to an NPN transistor gated with a 3.3KΩ base resistor to act as a switch. The data stream turns the 2N4401 hard on or off depending upon the coded state. This in turn switches on and off the Monsanto MV5000 series infrared LEDs. Three of the LEDs are used to make aiming at the receiver easier.

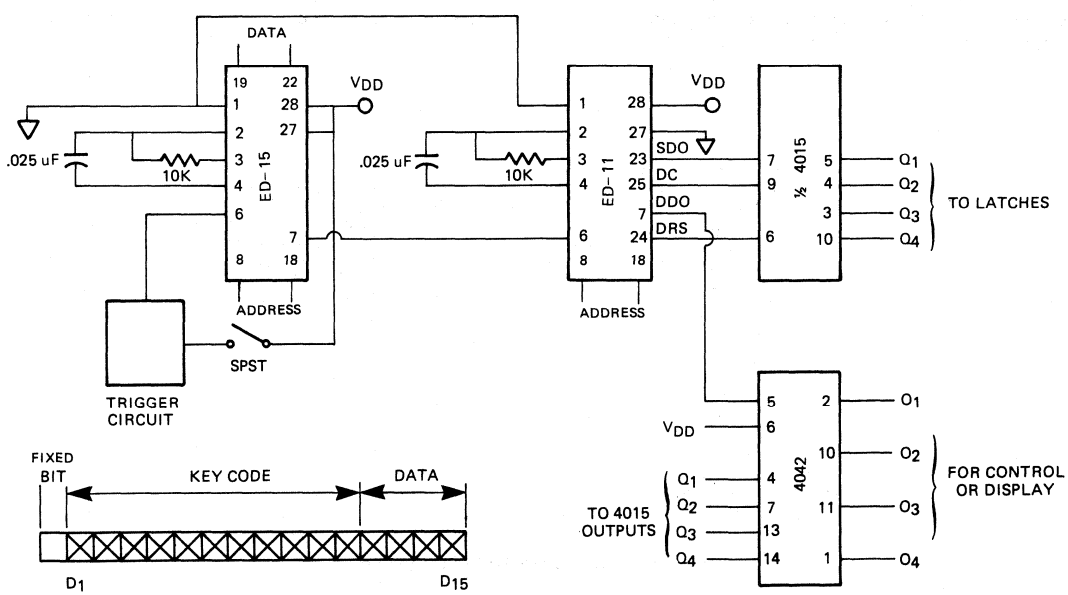


Figure 2. ED System with Latched Parallel Data Out

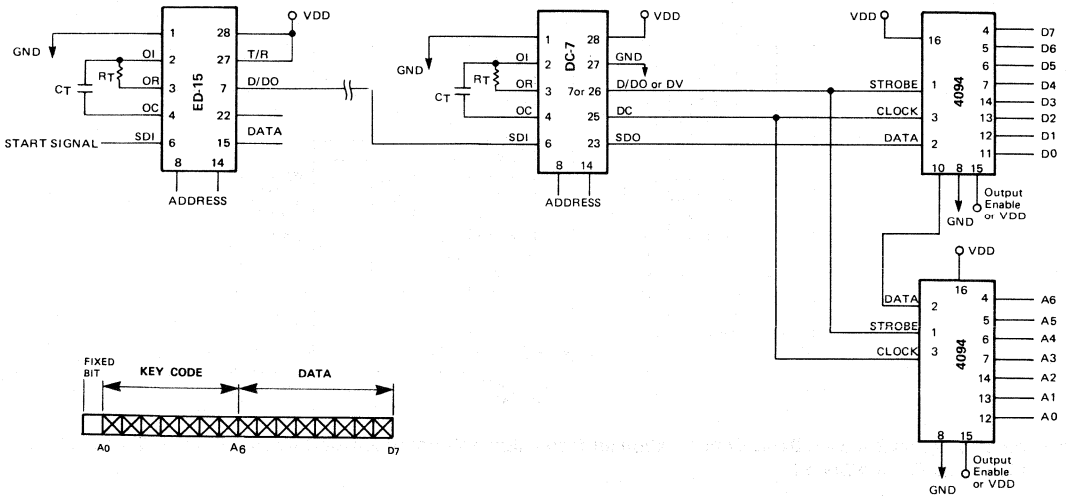


Figure 3. DC-7 System with Latched Parallel Data Out

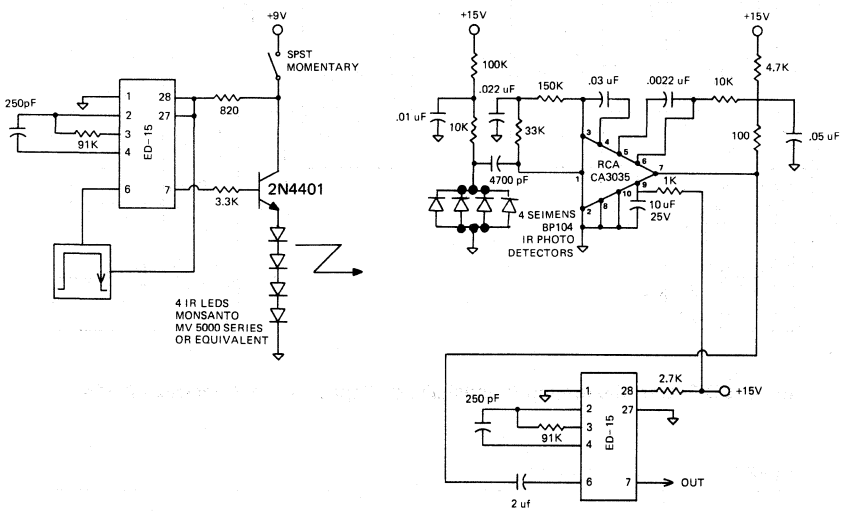


Figure 4. IR Remote Control Transmitter/Receiver

The receiver circuit consists of a three-stage amplifier (the CA 3035) with Siemens BP104-IR photo diodes arrayed for maximum coverage of the reception area. The output of the CA3035 is then applied to the ED-15 receiver chip and the signal is decoded in the normal way. The range of this set-up should be about 10 meters.

Even though in this application the ED-15 is shown, it will work equally well with any of the other ED ICs. This application can be combined with the application in Figure 2 to provide 4 bits of parallel data or Figure 3 to provide 8 bits of parallel data to operate displays, relays, etc.

Microprocessor Interface to ED-11, ED-5

It is possible to use the ED-11 and the ED-5 in conjunction with an 8-bit microprocessor to remotely control functions at a distance.

Because of the Supertex ED system's "single chip" approach to encode-decode remote control, it is possible to use these ICs in a "hand-shaking" arrangement, allowing for 2-way communication between 2 or more microprocessors with a 4-bit data word. To do this, an 8-bit µp is required, 4 bits are used as data, and the remaining bits control the EDs and and associated logic required to change the system from a data transmission system to a data receiving system.

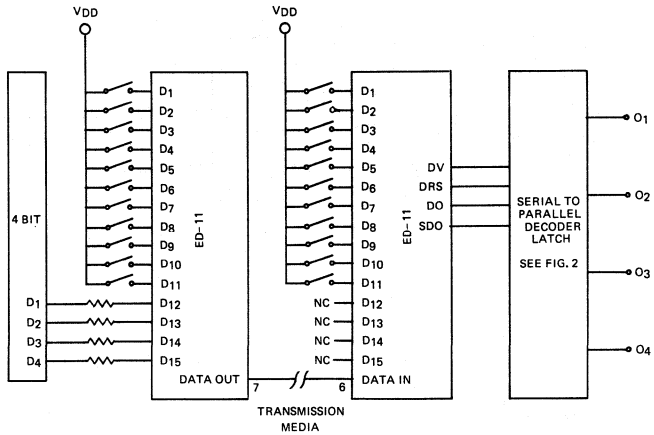


Figure 5. Block Diagram Showing Basic Configuration for Transmitting Microprocessor Data over Remote Control System Using ED-11s as Encode/Decode

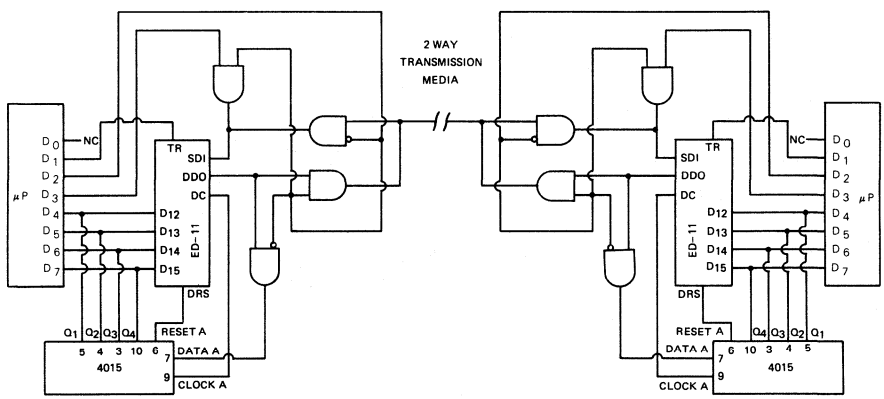


Figure 6. ED System Illustrating "Handshaking" Capabilities of Supertex ED-11s

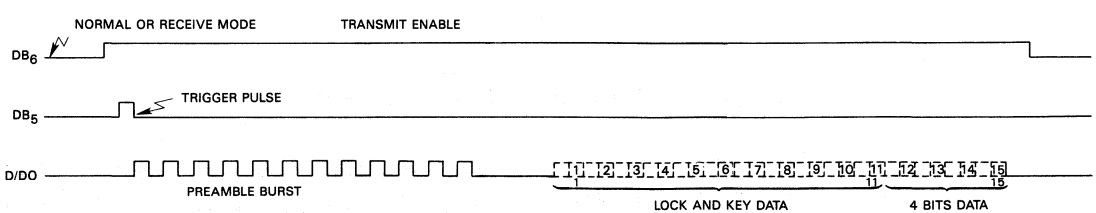


Figure 7. Possible Timing Diagram for Circuit Shown in Figure 5.

In Figure 6, an 8-bit microprocessor such as a 6502 or 6800 is used to enable the ED-11 or ED-5 to transmit data to another 8-bit microprocessor telling it to perform some function. When the transmitting μP is finished sending its message, it returns to the "receiver" mode. The interrogated μP then performs its function and switches itself to the "transmit" mode and sends confirmation back to the first μP.

In Figure 7, a "possible" timing diagram is shown for such an application. One can see that DB6 or transmit enable is actuated first. With all of the gates shown in Figure 6 now in the "transmit" mode, DB5 sends out a trigger pulse to the ED chip. This initiates a data transmission (shown as D/DO in the timing diagram). At the end of this data transmission DB6 drops back low, returning the ED and data systems to the "receive" mode. For RF transmission the DB6 signal can also be used (via a buffer) to drive a relay to key the RF transceiver to the transmit mode. The μP software for such an application would have to be developed by the user, and the circuit diagram shown here is only a suggestion. Microprocessor information used in this circuit is from the 6502 or 6800 literature and assumes its use.

ED "Carrier Current" One-Way Remote Control System

In the following application (Figure 8), the AC power lines running through a house or office building are used to transmit data from one ED to another. Such a system is an ideal way to interconnect multiple smoke alarms, turn on or off appliances from a central location, or monitor energy use in the home or plant.

This particular circuit (Figure 9) utilizes 160KHz as the transmission frequency. The reason that this frequency is used is that it has been shown that "around" 160KHz is the best compromise between noise and capacitive attenuation of typical building wiring. One of the major problems with "carrier current" communication devices is that house wiring is a very difficult transmission medium. Most building codes require that buildings be wired with a large two-conductor solid wire called "ROMEX." Since both conductors are jacketed together, the capacitance between them is quite high and the attenuation of high frequencies is considerable. To compound this problem many building codes require that the wiring be conduited. This will be found mostly in commercial

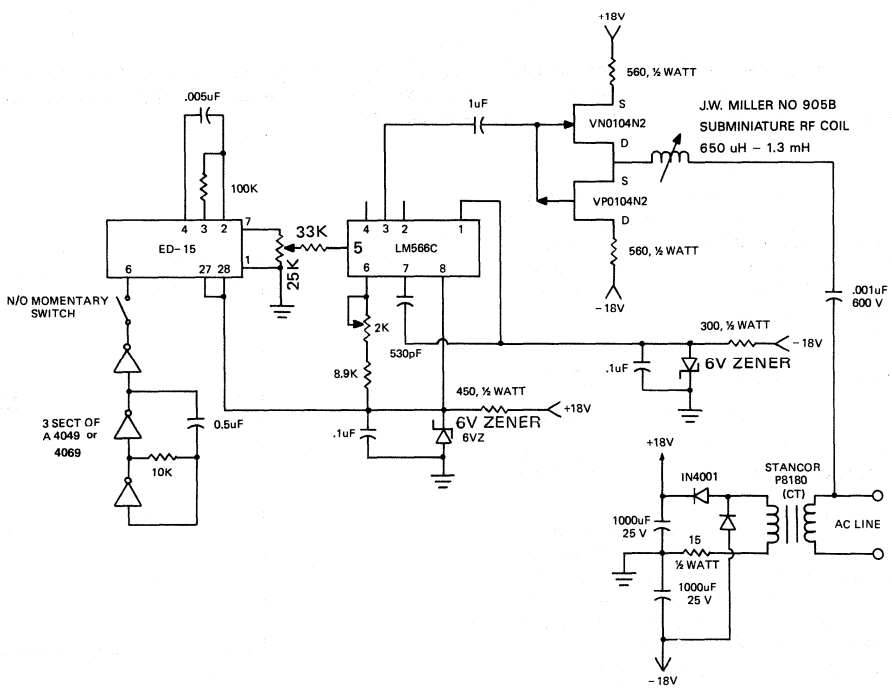


Figure 8. Carrier Current Transmitter

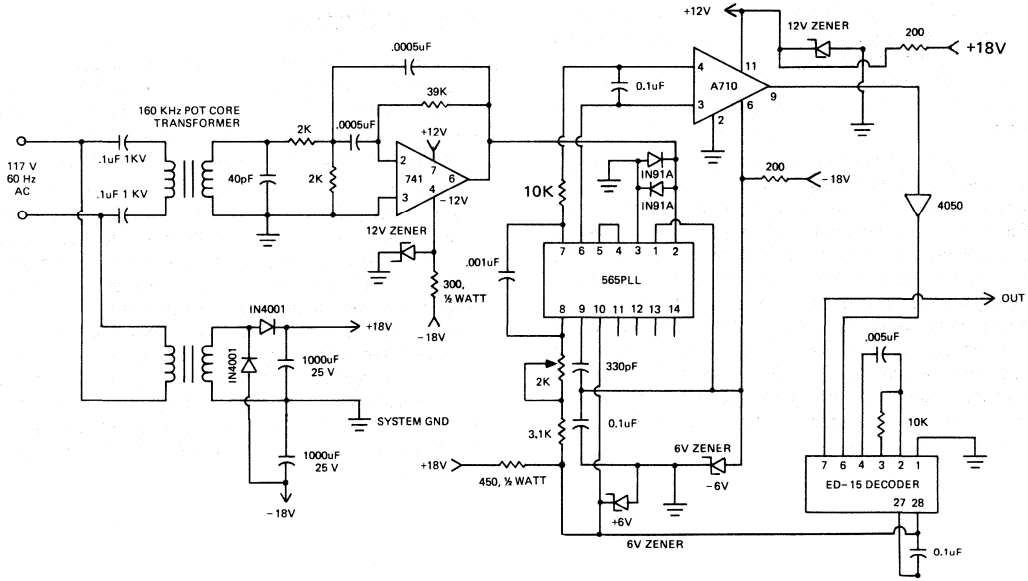


Figure 9. Carrier Current Receiver. 160KHz transformer consists of a 18 x 11mm ungapped pot core (Siemens, ferrocube, etc.) utilizing magnetics incorporated type "F" material wound with 80-1/2 turns of No. 35 wire for the secondary and 4-1/2 turns for the primary. This gives a turns ratio of approximately 15 to 1.

and multiple-dwelling buildings, but since the conduit is ground, the capacitance is even greater. Another problem with building wiring as a communication medium is the fact that many appliances hooked to the wiring are large inductive loads (motors, power transformers, etc.). When these inductors are in parallel with the ROMEX, very effective high frequency filters are formed.

External Oscillator for ED-15, ED-11, ED-5, DC-7

Often it is desired to drive the ED-series devices with an external clock. Due to external considerations it is not recommended in the general case.

However, the ED-15, ED-11, ED-5 and DC-7 device types may be externally driven in the transmission mode if certain precautions are taken. Using the circuit in Figure 10 will allow driving of the transmitter chip. The external oscillator MUST be gated on only during the transmission time after the START pulse. During all other times the O/I pin MUST be held high. The DRS signal in the transmit mode is a convenient signal to use as a gate for this purpose. A 1KΩ resistor in series will minimize possible current spikes inside the device. The gates shown in Figure 10 should be CMOS logic and share the same V_{DD} used on the ED device.

The synchronizing characteristics of the ED series in the receive mode do not allow an external oscillator to be used. The use of the data sheet curves will allow calculation of the resistor and capacitor network to use on the receiver to match frequencies with the external clock of the transmitter.

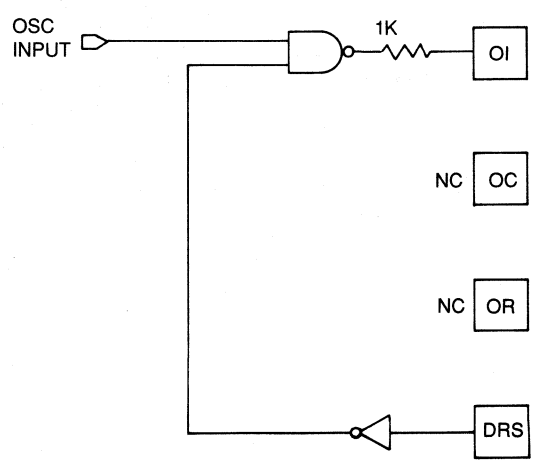


Figure 10. External Oscillator Gate for ED-15, ED-11, ED-15, DC-7A Transmission mode only.

Encoder-Decoders for Power Line Carrier Remote Control

Power Line Carrier Communication is starting to emerge as a viable, cost effective means for control and information exchange in both consumer and industrial applications.

Energy Management Systems for heating, air conditioning and lighting control are obvious examples of the use of the power line as a communication link. A system is shown in Figure 1 using Supertex Encoders and Decoders for transmitting and receiving control information over the power line. The prototype system was designed to allow remote On/Off and brightness control for a fluorescent lighting fixture using a dimming ballast. The design was simple and implemented in about a week's time.

System Description

The system uses an ED Encoder-Decoder chip set to generate the Power Line control messages and to decode the messages for appropriate action. The system transmitter is able to selectively address 32 different receivers and transmit 16 different control commands to the receivers that are connected to the AC power line.

The control message is coupled to the AC power line by a Signetics NE5050 Power Line Modem. The modem takes a serial bit stream, generated by the ED-9, and turns it into a series of 125KHz bursts. Each burst represents a digital "1" in the serial bit stream. This series of 125KHz bursts is transmitted over the AC power line to any receiver that is coupled to the AC line.

The series of 125KHz bursts are received by a second Power Line Modem and translated back into the original serial bit stream generated by the ED-9. This serial bit stream message contains address and control information. The message is decoded by an ED-5 to determine address match and control command. If the address does not match, then the rest of the message is ignored.

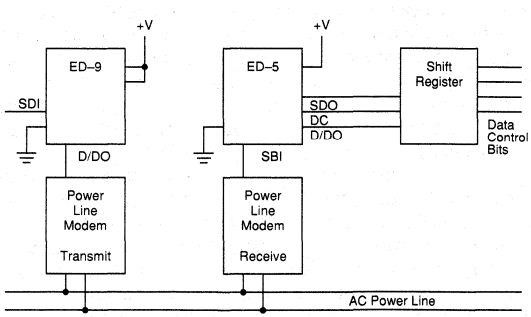


Figure 1. System Diagram

When there is an address match at the receiver, the ED-5 will serially transmit the data information into the serial to parallel shift register. The data can then be decoded to determine which of the 16 control commands was transmitted.

Transmitter (Figure 2)

The ED-9 performs address matching only. In this application, the 9 bits that are available for addressing are split into 5 bits of address (D4,D5,D6,D7,D9) and 4 bits of control data (D12-D15). The 5 bits of address are set with dip switches, and the 4 data bits can be set with dip switches or a rotary selector switch.

The transmission of a message is initiated by a pulse on the Start/Data input (SDI). The message baud rate, f_c, is determined by the RC combination of 10K ohms and .039uf at the OI, OR, and OC pins of the ED-9.

$f_c = 0.375/RC = .961KHz$
$T_c = 1/f_c = 1.04ms$
Data Bit Width = $2T_c = 2.08ms$
Data Clock Width = $0.5T_c = .52ms$

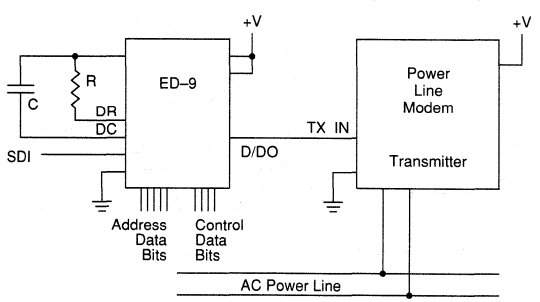


Figure 2. Transmit Circuit

Message Format (Figure 3)

The message (shown in Figure 3) consists of a preamble burst and a data transmission. The preamble burst is used to synchronize the receiver with the transmitter.

The data transmission consists of 15 bits of information. In this application only 5 bits are used for address information and 4 bits for control information. The data transmission is Manchester encoded. Manchester coding uses the transition from low to high to represent a binary "1" and a transition from high to low to represent a binary "0". With this technique, the first half of each data bit time is always the logical inverse of the second half. This

provides for a level transition during each data-bit time, and allows a synchronized receiver to easily read the correct data, even when large noise spikes are present.

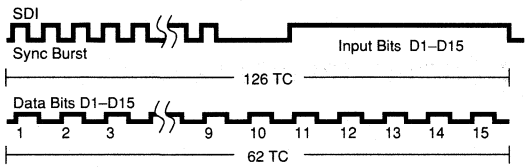


Figure 3. Message Format

Receiver (Figure 4)

The receiver uses an ED-5 in the receive mode by first checking the address of the incoming message against the preset 5-bit address in the receiver unit. If the address in the message matches the receiver address, then the 4-bit control data is serially shifted into the serial-to-parallel shift register. This 4-bit word is now available for further decoding and control.

The message enters the device on the Start/Data Input (SDI) pin. the ED-5 then matches the message address information with the address of the receiver, and if the bits match, the Decode/Data Out (D/DO) pin goes high until the next stream of serial data arrives at the SDI pin. D/DO going high pulses the strobe input to the CD4094. This action resets the shift register, and the DC output from the ED-5 clocks the entire message into the shift register. The last four bits of the message (D12-D15) contain the control information (refer to Figure 5). The control information will be at the outputs of the shift register (Q1-Q4) at the completion of the receive sequence.

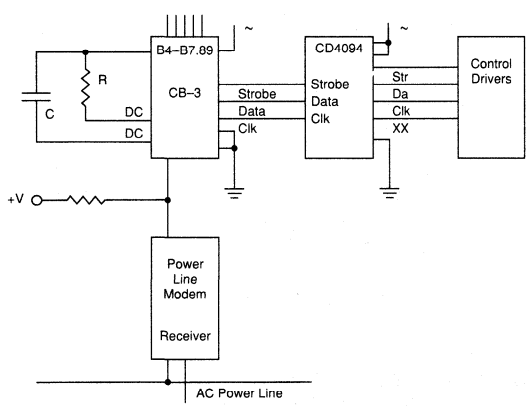


Figure 4. Receive Circuit

Power Line Interface

The Power Line Modem was calibrated to transmit a 125KHz burst at a signal level of 7.5 volts p-p into a 50 ohm load. Impedances of residential wiring may be over 50 ohms while industrial impedances may be less than 1 ohm, with the receiver sensitivity set at 15 millivolts.

The AC Power Line

The constraints imposed by the power line interface dictate the overall system operation. The power lines are a hostile environment for signals. The noise on the power line can be put into two categories: broad band and impulse. The broad band noise levels vary from a few to hundreds of millivolts. Impulse noise levels can range from millivolts to tens of volts. Examples of noise sources are light dimmers, universal motors, hair dryers, induction motors, radio and television receivers, and fluorescent lights. In general, noise levels in a factory environment will be much greater than in a residential environment.

The system described in this application note can, depending on the noise level, be affected by impulse noise on the power line. The communication link between the transmitter and receiver is an open loop one way command link. An impulse could cause false command decode if the impulse happened at the time when the receiver was decoding the control data section of the data transmission. The receiver would have to have properly received and decoded the address for the command to be improperly executed.

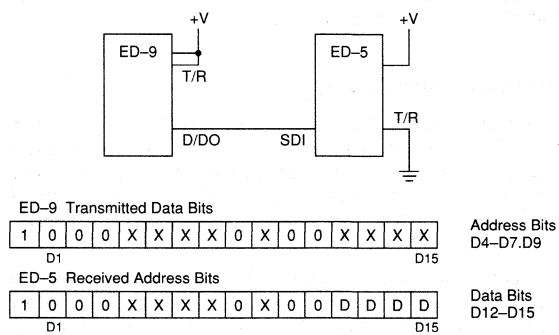


Figure 5. Data Patterns

Impulse noise could also cause errors in the address section of the data transmission, in which case the control command would be ignored due to improper address match. The effect of impulse noise on the operating system is not as much a problem with the encoder/decoder section but with the power line modem, which is improperly decoding the 125KHz bursts.

The impedance of the line is likewise ill-defined. It may be resistive, inductive or capacitive. Line attenuation is difficult to estimate because it is extremely load dependent. A high-power load can significantly reduce the impedance of the line at the point of connection and thus dominate attentuation for all points of communication that occur beyond the offending load unless that load is isolated with chokes. Capacitive loads can be equally troublesome and are not necessarily associated with high-power loads. Another large component of the net attenuation can be the signal loss incurred in coupling across the multiple windings of a power distribution transformer. This alone can amount to 20 to 40 db, depending on carrier frequency and transformer construction. The system described in this application will have problems communicating to the receiver units if the line attenuation is large enough to load the transmitted signal to a level below the receive sensitivity of the power line modem.

Designing for the Power line Environment

The application described in this paper is a relatively simple use of existing technology to achieve a low cost means of control communication over the AC power line. The system is very flexible with regards to the ability to add microprocessor intelligence to the transmit and receive ends of the communication link. This added intelligence may be used to overcome some of the problems associated with power line noise.

The microprocessor could be used to allow both receive and transmit at the same location. The microprocessor would enable the use of a closed-loop communication link with the unit that is to be controlled. This ability could be used to obtain status reports from the control unit, to make sure the unit properly responded to control information. In the case of a unit not properly responding to control messages, the controller would simply resend the control message until the unit properly responds. The microprocessor software could also include algorithms that detect power line noise or other power line communication. When noise or communication is detected, the microprocessor would simply wait until the power line was quiet enough for it to transmit its control message.

There are numerous methods for overcoming the problems associated with power line impedance. If the problem is due to the transmitted signal level, then line drivers can be added to boost the transmitted signal level. If the problem is due to cross phase attenuation caused by transformers, then a capacitor can be used to couple the communication signal across the windings.

The primary problem that everybody is faced with when interfacing to the power line is that the communication media (power line) is different at each installation. The key is to offer a system that is flexible enough to adapt to the demands of the environment.

Summary

Flexibility of the Supertex Encoder-Decoder devices can be utilized to make practical a simple power line interface design that has the capability to transmit data bidirectionally as well as the simple address match On/Off function. This design is only a representation of the many possible new product designs that can result from the use of the Supertex Encoder-Decoder in power line

Encoder-Decoders for Telemetry and Control

Todays industrial environment is the site of a modern revolution - the newest technology in control electronics is available for even the simplest task, at a reasonable price. New techniques of measurement offer increased speed and accuracy with low-cost simplicity. But, interfacing these components in the electrically noisy environment of a modern factory has proved to be a difficult problem. Motors, switches and other high-voltage, high current components used in a factory create a difficult environment for the transmission of the digital signals of the new electronics technology.

A device for maintaining digital data integrity while allowing simple transmission in a factory environment is needed. This device should be easy to interface with (or without) a microprocessor, offer serial transmission to minimize wiring, and be inexpensive. Additional features would include address recognition, so that several devices could be attached to the same control loop, and two-way communication capability.

A family of products meets these requirements. Designed originally for garage-door openers, this series of Encoder-Decoders has performed in many control and telemetry applications, including control loops, cordless phones, security systems, wildlife tracking, pagers, etc. Control loops are addressed here.

Device Description

ED Encoder-Decoders use an address-matching technique. They use CMOS technology to provide low power consumption for battery-operated systems.

Table 1 lists the basic characteristics. The ED-9 performs address-matching only, in the smallest package for lowest cost. The DC-7 allows a combination of 7-bit data transmission for microprocessor applications.

All can be used in either the Transmit or Receive mode by changing the logic level of the T/R pin. This allows the same device to be switched for two-way communications, thus reducing the cost and parts count.

The devices have an on-chip oscillator, using only a resistor and capacitor to set the clock frequency for device operation. The basic clock frequency is 20 kHz, with a serial transmission frequency being 1/4 that. The actual data flow rate, which must allow for preamble and delay times, works out to be one "word" every 6.7 ms.

Device	Number of Address Bits	Number of Data Bits	Serial Output
ED5	5	0	Yes
DC7	7	8	Yes
ED9	9	0	No
ED11	11	4	Yes
ED15	15	0	Yes

Table 1. ED Series of Encoder-Decoders

Data Transmission

The data transmission for the ED family is a 15-bit serial data "packet" with a 12-bit preamble. The data is Manchester encoded to provide noise immunity.

Manchester code (as implemented in the ED series) divides the time for each data bit in the serial string into two halves. A binary 1 becomes a transition from low to high; a binary 0 becomes a transition from high to low (Figure 1). The first half of each data bit time is always the logical inverse of the second half. This provides for a level of transition (high-to-low or low-to-high) during each data-bit time, and allows a synchronized receiver to easily read the correct data, even when large noise spikes are present. Figure 1 illustrates the Manchester-encoding method.

Each preamble burst, which is sent before the data bits, consists of 12 consecutive bits. The preamble is sent because the receiver of the transmitted signal, another ED family device, has no way of inherently synchronizing with the transmitter. The preamble burst allows a digital phase-locked loop (used in the Receive mode) to "lock in" to the transmitted signal. Then, when the actual data arrives, after the preamble, the Receive device can correctly extract the data from the bit stream. The Receive device also generates a clock signal which is in phase with the data stream (described later).

In the Transmission mode of operation a pulse on the Start/Data Input (SDI) will initiate the transmission of the data packet. The device will send a complete data packet (preamble and data) for each pulse on the start pin.

In the Receive mode, three functional options are available, depending on which device is selected: address matching, data recovery, or a combination of the two. All devices, when enabled in the Receive mode, accept a serial data packet generated by any other ED device. The serial data enters the device on the Start/Data Input (SDI) pin. The 12-bit preamble burst, which arrives first, is routed to the digital phase-locked loop to start and synchronize the R-C oscillator on the device. The 15-bit data word is the next to arrive. This is where the functional types differ.

Matching Operation

In the Receive mode, the data input pins are used to input data to be matched with the data received from the serial transmission. Each device is designed to "match" a different number of bits. If the bits on the data pins exactly match the received data, the Decode/Data Out (DDO) pin goes high until the next stream of serial data arrives at the SDI pin. If the data bits do not match, the DDO pin remains low. This is how the original application to garage-door openers was implemented, and it is the only function that the ED-9 can perform. As shown in Table 1, the ED-9 has no serial data output.

Courtesy Measurement and Controls Magazine

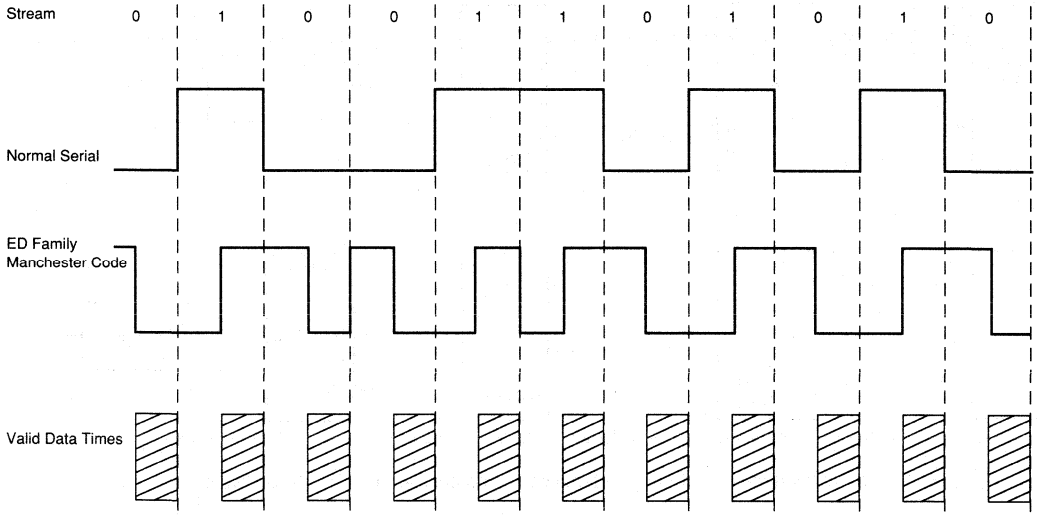


Figure 1. Manchester code converts a binary 1 into a low-high transition, and a binary 0 into a high-low transition.

Data Recovery

All the other ED series devices (ED-15, ED-11, ED-5, DC-7) can be used for data recovery. In these, the received data is carried through the device unaltered, and output on the Serial Data Out (SDO) pin. At the same time, the clock signal is output at the Data Clock (DC) pin. The leading edge of each clock pulse is situated during the time that the data on the SDO pin is correct (valid). The data clock signal can thus be used to load the correct received data into an external shift register for other uses.

This function does not depend on the data-making function, and can be used regardless of whether the data on the data pins matches the received data. When a data word is received, matched or not, the Data Valid (DV) pin goes high to signal the reception of a complete data word. This signal can be used to signal an awaiting system that data is present in the shift register.

Two of these devices (ED-11, DC-7) can use both functions simultaneously to achieve more capability. Both have 15 data input pins, one for each data bit in the Transmission mode. In the Receive mode, however, not all 15 data input pins are matched to the incoming data. In the ED-11, only the 11 most-significant data bits are matched; the 4 least-significant bits are ignored. The DC-7 matches only the 7 most-significant bits of the data; the 8 least-significant bits (1 byte) are ignored. This allows these devices to be used to transmit data (4 bits or 8 bits) to a receiver that is selected by the matching codes (11 bits or 7 bits). The use of this capability will be explained.

Communication media can be via (1) RF transmission (as in garage-door openers), (2) a long direct wire hookup, with digital line drivers, (3) infrared optical link or (4) fiber optic line. Use of the devices is independent of the communication medium used; presentation of a digital serial signal to the receiver input is all that is required. In the following application examples, although one particular communication medium is described, others could be substituted wherever desired.

Microprocessor Interfacing

ED devices are easily interfaced to microprocessor systems for either transmission or reception. If you are working directly with the microprocessor device and using assembly language, the task is made simpler because the microprocessor is fast compared to the ED devices. For data transmission, direct hookup to a Peripheral Interface Adapter (PIA), of the correct number of parallel bits to correspond to the data input pins on the ED device is the simplest interface. An alternative would be using one output from a PIA into a serial shift-register corresponding to the ED data input pins. A simple start pulse generated by the microprocessor after the data bits are set will then send the data out. Figure 2 illustrates these methods.

For the Receive mode, several types of interface are possible, depending on the receive function required. For address-match recognition only, the Data Input pins would be set by manual dip switches, and the Decode pin DDO would be connected to the microprocessor, either on a PIA pin or an Interrupt input. This would tell the microprocessor that a transmitter had called its' "name".

For reception of data through an ED device to a microprocessor directly, the ED device would be connected to a serial shift register through the SDO and DC function, to latch the data into parallel format. This shift register would be connected to an input PIA. Either the Data Valid (DV) or Decode (DDO) signal would be used to signal the microprocessor (via an Interrupt input) that data was available to the PIA. The DDO signal would be used only with the ED-11 or DC-7, which combine the matching function with data transmission.

An alternate method of interfacing the ED series device to a fast microprocessor is to connect the serial data output directly to a PIA pin, and use the Data Clock (DC) output as an interrupt to tell the microprocessor that the nest data bit is available. Fast response is necessary in this case.

A third method of interface for data reception is to use a tri-state output shift register, attached directly to the data bus of the microprocessor. An interrupt input from the DDO or DV will let the microprocessor read the data from the shift register in a similar manner as data is read from memory.

These are some of the more common interface possibilities available. Interface to a bundled system where an external parallel port is used may limit input flexibility due to the software overhead involved in using higher-level languages, but effective interface is still easily accomplished.

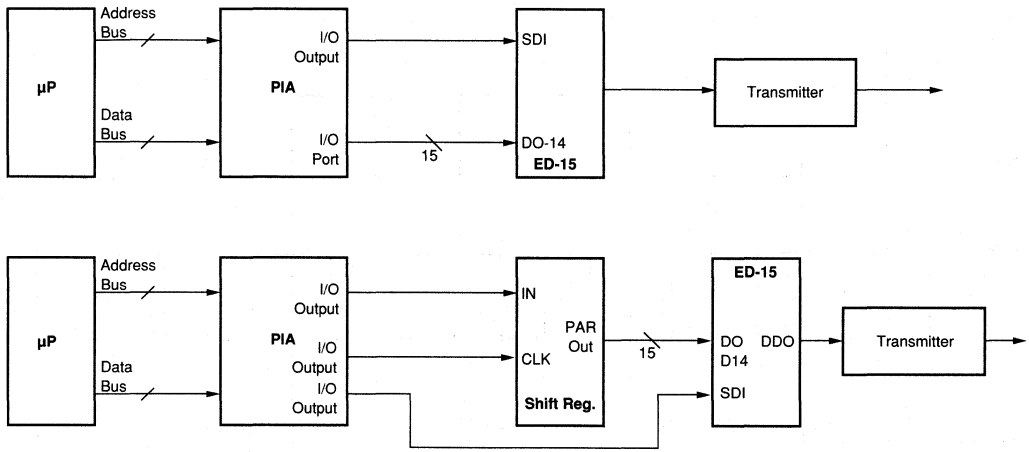


Figure 2. Peripheral Interface Adapter (PIA) interfaces microprocessor and ED-15 for data transmission.

Basic Systems

The simplest use of the ED device is where one transmitter is used with one receiver. For address matching (such as a garage-door opener), the devices are used as shown in Figure 3. The start pulse is generated by a simple push-button. Switch bounce is not a problem because these devices "restart" the transmission each time the SDI pin pulses. Therefore, the last "bounce" will send a complete data packet, which will be received correctly. When the transmission is completed, the Data Valid (DV) pin goes high to signal a successful reception of a correctly formatted signal. If the input data stream also matches the receive device Data Input pins, the Decode Output (DDO) pin also goes high at this time.

A similar simple application for data transmission would use an ED device with serial Data Output and Data Clock to allow data collection at the receiver. In Figure 4, one DC-7 and one ED-15 are used, with the data byte latched into a 4094 serial-to-parallel shift register.

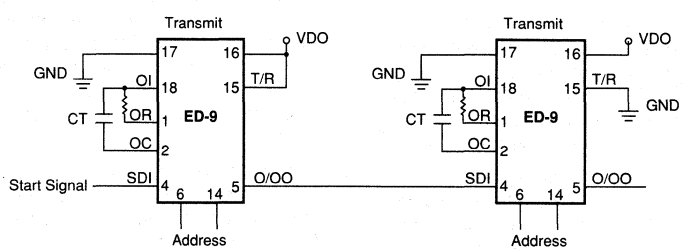


Figure 3. Address matching use.

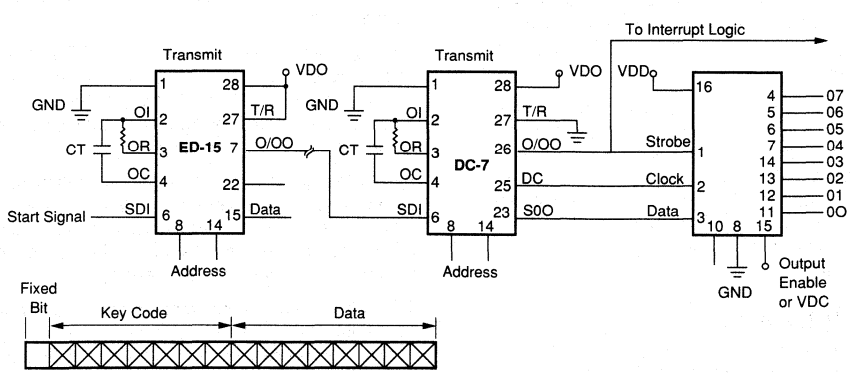


Figure 4. Addressed data transmission. Data is loaded into a shift register and latched if the transmitted address matches the receive address.

Multipoint Control Network

ED-11 or DC-7 devices can be used to implement a simple, low cost multipoint control network using a serial loop daisychained to each controlled system. Figure 5A illustrates this interconnect scheme. One transmission device is connected to a common serial data bus with multiple receivers, one per controlled system. The number of receive devices possible is determined by the number of address bits implemented in the transmit and receive devices. The DC-7 can address 128 receivers; the ED-11 can address 2048 receivers.

The transmitting ED device in this type of network is normally connected to a microcomputer of some kind, while the receivers may interface directly to the controlled system. In operation, the microprocessor will select the data word to initiate the desired function in that system. This information is then placed on the Data Input pins or the transmission ED device, and a Start pulse applied to the SDI pin. The serial transmission will be received by all ED devices in the network; however, only the device with a similar address pin code will match and raise the DDO pin high. The SDO pins of the receiver EDs are each connected to serial-parallel shift registers to capture the data word portion of the transmission. The system with the address match will read the command word form the shift register and execute the command.

The serial wire loop is only one implementation of this type of control network. A multipoint "star" type of network (Figure 5B), ideal for a factory floor where visibility is good, could be implemented easily using an infrared transmitter at the control station. Each receiver station would use a infrared detector to receive the signal; no wiring is necessary. Additional receive stations are easily added to the network.

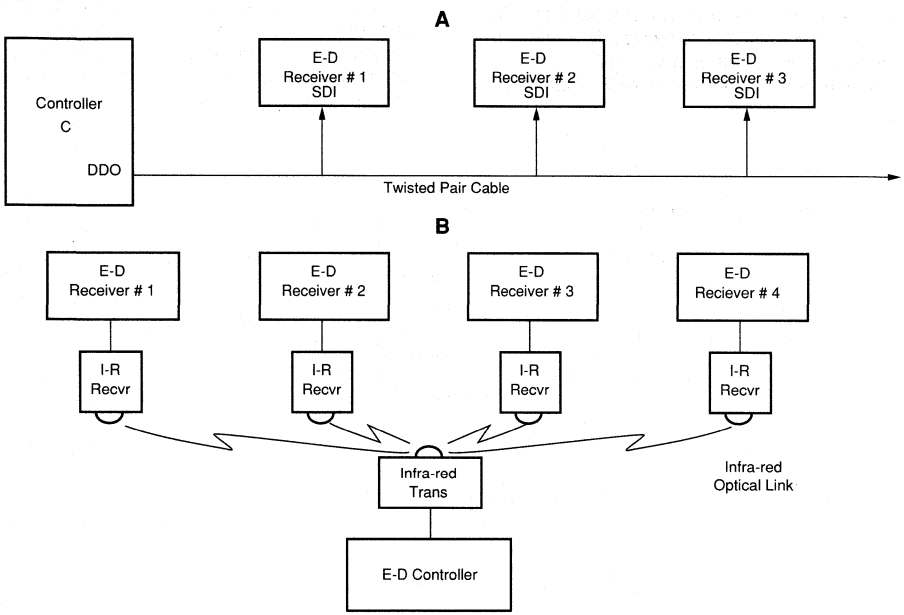


Figure 5. Multipoint one-way control network.

A Bidirectional Network

An enhancement to the network described in the previous section is to implement two-way communication. Many applications require this flexibility, where a controller needs to monitor the status of a remote system, or have a remote instrument make a measurement and report the results to the central controller. This type of network, where the controller sends out a request and receives a response, is called a "polled" system; it is the simplest way to implement two-way communication. No interrupt conflicts are involved, and the controller selects the priority in which the controlled systems are queried.

The capability of ED devices to be switched between transmitter and receiver allows low-cost implementation of two-way communication with a minimum number of parts. Using a microprocessor with the ED data input pins attached to a Peripheral Interface Adapter (PIA) port is the simplest method, although discrete logic is usable for less complex requirements. Figure 6 shows one possible configuration.

The interaction between a controller and a remote system is straightforward. The controller will transmit an address and data word, as in the one-way network explained previously. It will then switch the ED device to Receive mode, connecting the SDI pin to the network transmission medium and monitoring the Data Valid (DV) pin for a signal that a transmission has been received. The SDO and DC pins of the controller are connected to a shift register to receive the information from the remote system.

The remote system, with its ED device in the Receive mode, receives the transmission from the controller and matches the address to the status of its Data Input pins. At the same time, the data word is latched into a shift register through the SDO and DC pins. If an address match is found, the remote system then takes the data word from the shift register and executes the command. If data or status is to be sent back to the controller, the remote system will then apply the data to be sent back to the controller on the Data Input pins associated with the data bits of the transmitted packet. The Decode Data Out (DDO) pin is connected to the transmission media, and Start pulse is applied to the SDI pin. The remote ED device then will transmit the address and data to the controller. The remote system transmits its own address back to the controller with the data to prevent other remote systems from receiving and decoding the transmission in error.

In this type of network interaction, some timing constraints must be met. The controller, when sending out a request and awaiting an answer, must have a time-out feature to prevent lockup of the system if the receiver does not receive the request. After the controller sends its message, it should wait an appropriate time and then re-send the message.

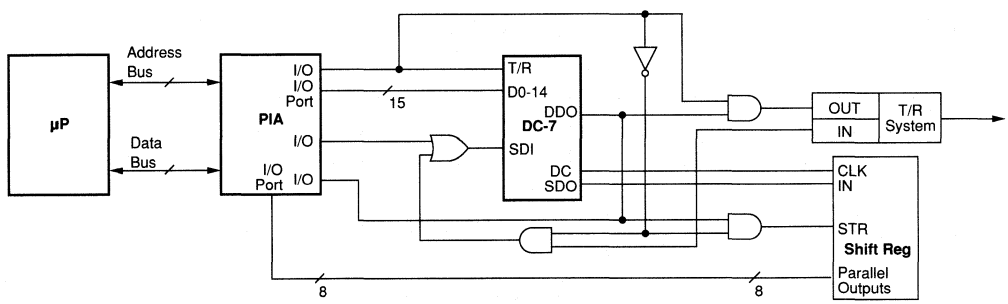


Figure 6. Bidirectional communication.

Supertex inc.

Static Handling and Testing Techniques For MOS Devices

CAUTION MUST BE USED WHEN HANDLING AND TESTING MOS DEVICES. STANDARD PROCEDURES SHOULD INCLUDE THE FOLLOWING TECHNIQUES IN ORDER TO AVOID POSSIBLE STATIC DAMAGE:

1. MOS devices must be stored in containers such as bags or tubes made of conductive and/or static dissipative material (DOD-HDBK-263).

2. The person handling the device should wear a wrist-strap grounded through a resistor of 1MΩ ±10%

3. Workstations should have grounded conductive mats over non-conducting surfaces.

4. All conductive surfaces and equipment must be connected to earth ground.

5. Rubber gloves, finger cots and clothing that are recommended to be worn by any person handling parts must be the type which does not generate electrostatic charges.

6. All parts should be handled by their packages and not by the leads.

7. Relative room humidity should be kept between 45 to 60% since static generation increases exponentially as humidity decreases.

8. Work, testing and storage areas should be mopped monthly with staticide solution or equivalent.

9. For further details refer to DOD Handbook 263 and DOD Standard 1686.

FOR YOUR CONVENIENCE, THE FOLLOWING IS A PARTIAL LIST OF COMPANIES THAT SUPPLY ANTISTATIC PRODUCTS:

1. 3M Nuclear Products 3M Center St. Paul, MN 55101	Conductive Bags, Grounding Mats, Tote Bins and Other Material
2. Wescorp/DAL Industries, Inc. 1155 Terra Bella Ave. Mountain View, CA 94043	Wrist Straps
3. Biggam Enterprises, Inc. 2124 Bering Dr. San Jose, CA 95131	Wrist Straps, Staticide and Other Antistatic/Conductive Material
4. Free-Flow Packaging Corp. 2500 Middlefield Rd. Redwood City, CA 94063	Anti-Static Packaging Material

Quality Assurance

The Management of Supertex Incorporated is committed to the continued enhancement of product excellence and service through the dynamics of its Reliability and Quality Assurance System, through the integrity of its people, and through the many professional disciplines engaged in new product development and process innovation.

It is the chartered responsibility of the Reliability and Quality Assurance Manager to oversee and ensure enforcement of Supertex's Quality System. A formal yearly review is undertaken to ensure continued development of a Quality System that maintains a competitive stance with the marketplace and meets customer requirements.

Primary Job Charter of the R & QA Departments:

In-Process QC – The primary responsibilities of the Quality Control Department are to establish and maintain effective controls for monitoring manufacturing processes and equipment; to provide real time feedback of information concerning the state-of-control; and to initiate statistically valid techniques to further improve quality and reliability levels. This concept is used extensively in, but not limited to, the following major Quality Control functions:

- Incoming Raw Materials
- In-process Wafer Fabrication
- In-process Assembly

Quality Assurance (Standard and Hi-Reliability) – The primary responsibilities of the Quality Assurance Department are to assure that the delivered product meets workmanship standards imposed for standard or hi-reliability products and/or special customer requirements. This is accomplished through a program of process controls and gate inspections designed so that all devices are properly tested and sampled prior to shipment. Real time feedback, concerning control/inspection data, keeps all relevant personnel fully informed on the quality level of product going through final test operations. Major Quality Assurance functions include:

- Incoming Contract Subassemblies
- Outgoing Wafer Electrical and Visual Inspection
- Product Assurance Electrical Test
- Plant Clearance

Reliability – The primary responsibility of the Reliability function is to assure that a high and consistent level of product reliability is continually being produced. The Reliability Department establishes, defines and maintains evaluation programs to determine process/product reliability. Major Reliability activities include:

- Failure Analysis
- Hi-Reliability Program
- Process/Product Qualification
- New Product Design Evaluations
- Reliability Assurance Monitors

Document Control – The primary responsibilities of the Document Control department are to translate and format internal operating procedures and customer requirements into a system of regulatory written instructions. Document Control functions to ensure documentation integrity by establishing and maintaining procedures for:

- Initiating, revising, approving, distributing, recalling, and archiving documents.

Organization

The Manager of Quality Assurance/Quality Control reports directly to executive staff level of Management.

Reliability Assurance Management maintains a dual level of reporting; with direct report to the R & QA Manager for R & QA program coordination and by dotted line to the Product Vice President respective of product service for Reliability Assurance support.

It is the responsibility of the R & QA Manager to administer the planning, organization, execution, surveillance, appraisal, corrective action and documentation of Quality Programs. The character, responsibility and authority vested with the R & QA Manager will establish the means to attain the necessary quality and reliability objectives in all aspects of manufacturing within the accorded guidelines of this manual..

Quality programs administered by the R & QA Department support the following functions:

Operator Training – Supertex maintains a System of Operator Training and Qualification specific to the nature and complexity of each manufacturing operation, inspection, or test requirement. The basic training approach used by Supertex is supervised on-the-job training assisted by experienced/qualified personnel to provide a "buddy system" of training.

Training is typically performed with the same equipment and tools used in the normal manufacturing environment. The use of training aids, such as films, photographs and demonstrations of equipment and tools, is typical.

Each department manager is responsible for the training and evaluation of the workmanship performance to manufacturing norms.

The R & QA department maintains a System of Audits/Monitors for evaluating Operator's adherence to specification and quality of workmanship.

Raw Material Procurement and Qualification – Supertex maintains a system that ensures economical control and conformance to detailed technical and quality requirements of purchased materials (direct and critical indirect). Material procurement is performed through regulated specifications and drawings. R & QA functions within this system by providing the following services:

- Documented instructions for material evaluation, procedures, flow, workmanship standards, test methods and statistical sampling.
- Incoming inspection of raw materials.
- Identification and segregation of qualified and nonconforming material.
- Vendor qualification and ongoing vendor performance appraisal.
- Feedback of inspection results and informing suppliers of new design changes on raw materials.
- Formal review for disposition of nonconforming materials.

Equipment Calibration – Supertex maintains a Calibration System that ensures measurement accuracy of equipment used to determine product workmanship and acceptability.

The Calibration System conforms to MIL-STD-45662. Major provisions of the R & QA program are described as follows:

- Qualification of external calibration services.
- Traceability of references to National Institution of Standards and Technology. Identifications of measurement and test equipment (electrical, mechanical, and optical) for type and frequency of calibration.
- Document file certifying equipment calibration and recall history.
- Management report on recall status.
- R & QA audits of equipment calibration (date stickers and recall designation).

Manufacturing Flow, Inspection, and Test Points – Supertex maintains Flow Charts that describe the sequential steps of semiconductor processing and associated documentation for Wafer Fabrication, Assembly, and Post Assembly Finishing through Final Outgoing Plant Clearance. Flow charts are prepared for each product family and associated manufacturing technology.

Flow charts that delineate Fabrication processing are regarded as proprietary and are not available for external dissemination without prior approvals from the R & QA Manager and respective Product/Operations Vice President. Applicable Assembly Packaging Flow Charts are Available upon request.

Flow charts for Customer Hi-Reliability Products are documented by a detailed lot traveler which defines all sequential operations, manufacturing inspection points, Customer Source Inspection points, and Quality Assurance product sample acceptance points.

In-Process Quality Control — Quality Control is a system of measurement and surveillance. The System is comprised of visual, dimensional, structural, and electrical characterization of material from incoming receipt of raw goods to outgoing finished product. Information obtained provides management with an overview on the state-of-the-process by specifically quantifying position of product yield, quality, and reliability.

Major elements found in Supertex's Quality Control Program are summarized by, but not limited to, the following:

- Environmental monitors (Airborne Particle counts, % RH and temperature).
- Routine Scanning Electron Micrography (SEM) of semiconductor devices.
- Specification compliance audits.
- Random monitor of wafers in-process.
- Electrostatic discharge prevention/monitor.
- Product lot sample qualification at critical manufacturing points.
- Wafer/die electrical sort monitor.
- Quality performance/trend data reporting.
- Return material analysis reporting.
- Monitoring of storage, handling, packaging, and identification of raw materials, of work-in-process, and of finished product.

Product Assurance Inspection – Supertex maintains a system of Product Qualification through inspection and test of finished product prior to customer shipment.

The Quality Assurance department provides inspection based on statistical sampling to ensure that outgoing product quality meets internal workmanship standards and customer procurement requirements.

The following process controls, inspections, tests, and documentation requirements are assured prior to submission of product to Customer Source Inspection and prior to final Outgoing Plant Clearance:

- Test equipment correlation and qualification.
- Monitor manufacturing test operations.
- Ensure conformance of product lots to detailed customer test requirements (Electrical, External Visual, and Mechanical).
- Assure proper and complete documentation for each product lot, both in-process and at-plant clearance.

Reliability Assurance – At Supertex the Reliability Concept is introduced at the design phase of all new products. The factors that may affect product reliability are: compatibility of fabrication process, circuit layout and characteristics, assembly process, package materials, and application. Hence, Reliability Engineering is involved in evaluating all critical factors of reliability, starting with the design and first prototype functional circuit. From analysis, modification of design, wafer fabrication, and assembly, process changes can be implemented to enhance the reliability of the product. Approval is given for the release of new product to manufacturing only after the reliability of the product is established as acceptable within standard norms.

The Reliability Department provides the Product Group with a number of programs to define product reliability levels. Among these programs are: 1) Qualification, 2) Reliability, 3) Failure Analysis, and 4) Data Collection and Presentation.

Qualification Program of New Products and Processes:

- Procedures for qualification of new product designs require Reliability participation and approval in design reviews, documentation, characterization, and reliability stress studies.

- New package qualification is approved and released for production by Reliability after prescribed environmental tests have been successfully completed.
- Qualification of a new product is granted only after Quality and Reliability have completed evaluation of process control studies. Significant modifications to existing processes are treated as new processes for the purpose of qualification.
- Proper documentation of all changes to process steps and procedure, and of any new or improved designs or material, is assured by Reliability's approval.

Reliability Monitor Programs:

- Device and Package Reliability Monitor Programs are effected for all packages using a variety of device types to maximize data usefulness and to evaluate cost effectiveness of equipment.
- Packages are evaluated using all applicable methods of MIL-STD-883; Class B, or MIL-STD-750, as appropriate. Data are reported, as specified, in detailed procedures for each package-chip combination. Package Monitor programs include, but are not limited to, the following general tests, using the appropriate conditions specified in MIL-STD-883, Class B, Method 5005:

Condition	Method
Operating Life (HTRB)	1005
Steam Pressure (Molded packages)	N/A
Temperature Cycling	1010
Package Hermeticity	1014
Intermittent Opens (Molded package)	N/A
Salt Atmosphere (Initial Qual, only)	1009
Constant Acceleration	2001
Mechanical Shock (Initial Qual, only)	2002
Solderability	2003
Lead Integrity	2004
Vibration (Initial Qual, only)	2007
Biased Temperature Humidity (Molded packages)	N/A

- Accelerated Stress Monitor Programs are conducted to obtain timely feedback for process evaluations, as well as for ultimate device capability studies.

Failure Analysis:

- It is the policy of Supertex to perform analysis of defective product and utilize the resulting findings to improve product yield and integrity.
- Reliability Engineering also performs failure analysis in mode and the mechanism of all failures (both from routine reliability tests and customer returns).

Failure Analysis Support Activities Include:

- Qualification of existing products for new applications.
- Customer Qualifications. Reliability is responsible for review and acceptance of all customer requirements. When qualification programs or special testing is required, Reliability designs and implements appropriate test plans and coordinates with customer.
- Failure analysis, in support of In-Process Quality Control monitors, is handled by Reliability through Failure Report Requests. This support includes such services as visual inspection, metalography, thickness measurements, selective etching, and die probing.
- Customer's requests for failure analysis are filled by Reliability, which coordinates all replies to customers and approves all correspondence outside the Company.
- Where Reliability has determined that corrective action is necessary prior to the release of product for shipment, or to proceed further in production processing, a Corrective Action Request is generated by Reliability. No shipment may occur if the integrity of product reliability would be jeopardized.

Reporting and Publication of Data:

Qualification test reports are prepared and distributed by Reliability for all certified products and processes which have been formally qualified and released for manufacturing.

Reliability is responsible for assisting the Marketing department in the preparation of publications for distribution to field sales locations and to customers.

Presently, the in-house Reliability Assurance testing is supplemented by testing done at outside Test Laboratories that have been approved by D.E.S.C. for performing MIL-STD testing.

In addition, Reliability Assurance maintains a routine monitor of commercial grade finished product to evaluate reliability attributes against internally published norms. Products and packages are deliberately selected to represent typical characteristics and conditions of manufacturing – with the following considerations given:

- Design complexity and fabrication processing technology.
- Package type/assembly construction and materials.
- Assembly plant location.

Supertex reliability data for standard product is published for internal use. Specific reliability information is made available to customers upon request.

Plant Clearance Inspection – Supertex maintains a Final Outgoing Inspection on Finished assembled/tested product to ensure that all conditions of processing have been satisfied and that support documentation, as specified by contract, is maintained for each shipped lot.

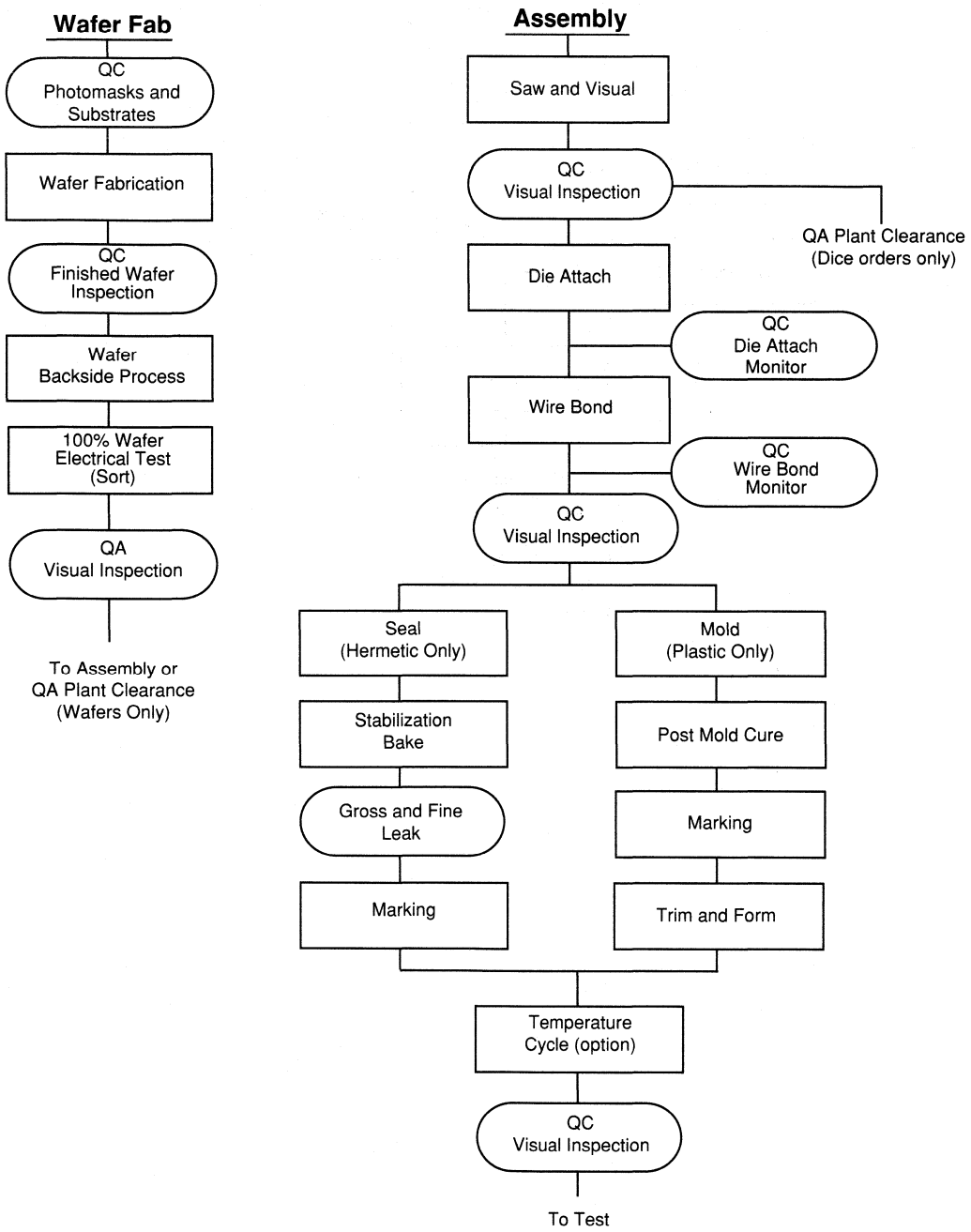
Provisions for the control of shipped product during the Outgoing Plant Clearance Final Acceptance Program are structured to ensure product workmanship guarantees are met.

Summary

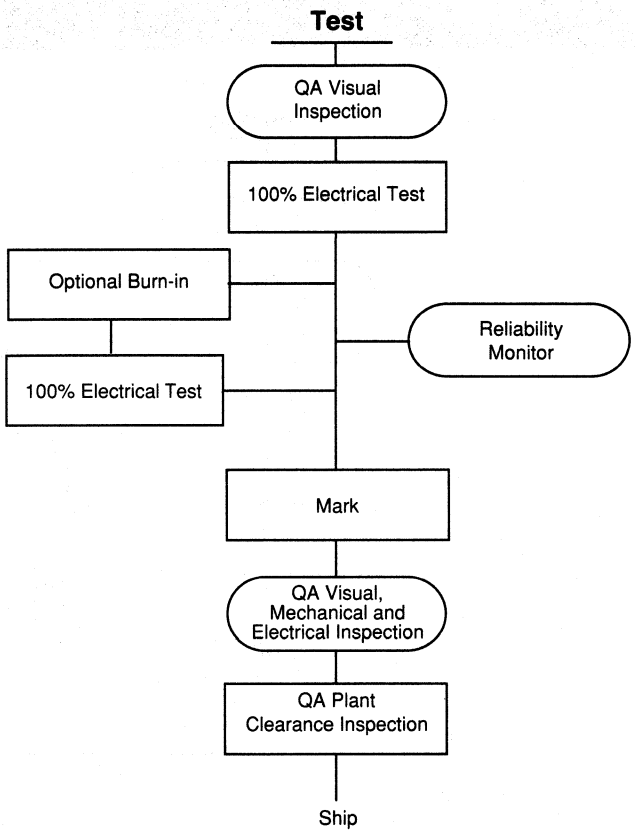
Supertex maintains R & QA Programs at critical operations to assure that products are manufactured under a documented and controlled system for consistency in workmanship standards (fit, form, function, and reliability).

The following Standards and Specifications have been integrated into Supertex's manufacturing operations and process control programs:

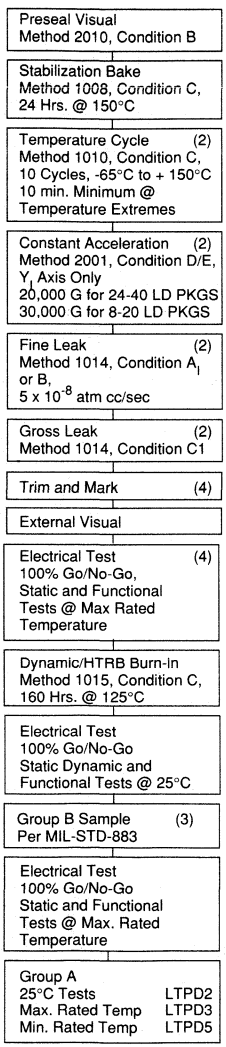
- FED-STD-209 Clean Room and Work Station Requirements, Controlled Environments.
- DOD-HDBK-263 Electrostatic Discharge Control Handbook for Protection of Electrical and Electronic Parts, Assemblies and Equipment
- DOD-STD-1686 Electrostatic Discharge Control Program for Protection of Electrical and Electronic Parts, Assemblies and Equipment.
- MIL-M-38510 Microcircuits, General Specification For.
- MIL-Q-9858 Quality Program Requirements.
- MIL-I-45208 Inspection Systems.
- MIL-S-19500 Semiconductor Devices, General Specification For.
- MIL-STD-105 Sampling Procedures and Tables for Inspection by Attributes.
- MIL-STD-750 Test Methods for Semiconductor Devices.
- MIL-STD-883 Test Method and Procedures for Microelectronics.
- MIL-STD-202 Test Methods for Electronic and Electrical Component Parts.
- MIL-STD-45662 Calibration System Requirements.
- Special Customer Specifications


Wafer Fab
QC Photomasks and Substrates
Wafer Fabrication
QC Finished Wafer Inspection
Wafer Backside Process
100% Wafer Electrical Test (Sort)
QA Visual Inspection
To Assembly or QA Plant Clearance (Wafers Only)
Assembly
Saw and Visual
QC Visual Inspection
QA Plant Clearance (Dice orders only)
Die Attach
QC Die Attach Monitor
Wire Bond
QC Wire Bond Monitor
QC Visual Inspection
Seal (Hermetic Only)
Stabilization Bake
Gross and Fine Leak
Marking
Mold (Plastic Only)
Post Mold Cure
Marking
Trim and Form
Temperature Cycle (option)
QC Visual Inspection
To Test (See Page 5-2)

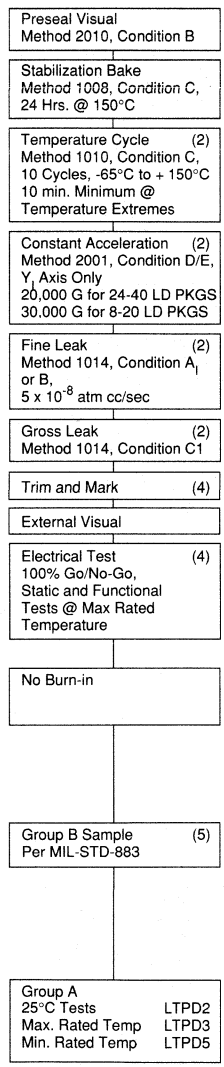
DMOS /HVCMOS Standard Product Flow



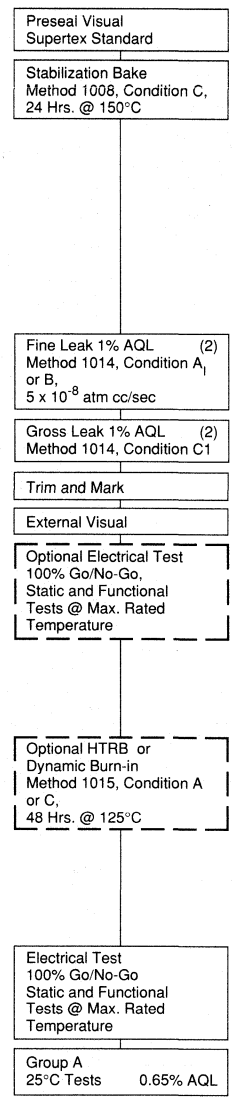
RB PRODUCT FLOW
(SIMILAR TO MIL-STD-883 CLASS B)



RC PRODUCT FLOW



COMMERICAL PRODUCT FLOW



Note 1: Processing consists of 100% screening and Group A. Generic group B, C and D data available on request.
Note 2: Hermetic packages only.
Note 3: Group C & D periodic lot sampling per MIL-STD-883.
Note 4: As required.
Note 5: No group C & D
All test methods are per MIL-STD-883 unless specified otherwise.

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DMOS Process Option Flow Chart

DMOS ARRAY RB FLOW[1] (SIMILAR TO MIL-STD-883 CLASS B)

1. Preseal Visual — Method 2010, Condition B
2. Stabilization Bake — Method 1008, Condition C, 24 Hrs. @ 150°C
3. Temperature Cycle — Method 1010, Condition C, 10 Cycles, -65°C to +150°C
4. Constant Acceleration (2) — Method 2001, Condition E, Y_1 Axis Only -20,000 G
5. Fine Leak (2) — Method 1014, Condition A or B, 5 x 10^{-8} atm cc/sec
6. Gross Leak (2) — Method 1014, Condition C_1
7. Electrical Test — 100% Go/No-Go, 25°C D.C. Parameters
8. HTRGB Burn-in (5) — Method 1015, Condition A, 48 Hrs. @ 150°C (optional, dashed box)
9. Electrical Test (5) — 100% Go/No-Go 25°C D.C. Parameters (optional, dashed box)
10. HTRB Burn-in — Method 1015, Condition A, 80 Hrs. @ 150°C
11. Electrical Test (Post burn-in) — 100% Go/No-Go 25°C D.C. Parameters
12. Group A — Subgroup 1 VIS/MEC, LTPD 5, Subgroup 2 D.C. @ 25°C LTPD 2(116/0), Subgroup 3 D.C. Min./Max. Temperature, LTPD 2(116/0), Subgroup 4 A.C. LTPD 2(116/0)

SX FLOW (SIMILAR TO JAN TX) / SXV FLOW[1] (SIMILAR TO JAN TXV) MIL-STD-750

1. Preseal Visual (6) — Method 2072
2. Stabilization Bake — Method 1032, 24 Hrs. @ 150°C
3. Temperature Cycle — Method 1051 25 Cycles, -65°C to + 150°C
4. Constant Acceleration (2) — Method 2006 Y_1 Axis only. TO-3 – 10,000 G, Others – 20,000 G
5. Fine Leak (2) — Method 1071, Condition G or H, Maximum Leak Rate TO-3 – 5 x 10^{-7} atm cc/sec Others – 5 x 10^{-8} atm cc/sec
6. Gross Leak (2) — Method 1071, Condition C
7. Electrical Test (4) — 100% Go/No-Go, 25°C D.C. Parameters
8. HTRGB Burn-in (3) — Method 1042, Condition B, 48 Hrs. @ 150°C
9. Electrical Test (4) — 100% Go/No-Go, 25°C D.C. Parameters
10. HTRB Burn-in — Method 1042, Condition A, 168 Hrs. @ 150°C
11. Electrical Test (4) — 100% Go/No-Go, 25°C D.C. Parameters
12. Electrical Test — 100% Go/No-Go, Group A, Subgroup 2
13. Group A — Subgroup 1 VIS/MEC, LTPD 5, Subgroup 2 D.C. @ 25°C LTPD2(116/0), Subgroup 3 D.C. Min./Max. Temperature, LTPD 2(116/0), Subgroup 4 A.C. LTPD2(116/0)

SJ FLOW (SIMILAR TO JAN) MIL-STD-750

1. Stabilization Bake — Method 1032, 24 Hrs. @ 150°C
2. Fine Leak 1% AQL (2) — Method 1071, Condition G or H, Maximum Leak Rate TO-3 – 5 x 10^{-7} atm cc/sec Others – 5 x 10^{-8} atm cc/sec
3. Gross Leak (2) — Method 1071, Condition C
4. Electrical Test — 100% Go/No-Go, 25°C D.C. Parameters
5. Group A — Subgroup 1 VIS/MEC, LTPD 5 Subgroup 2 D.C. @ 25°C, LTPD 2(116/0), Subgroup 3 D.C. Min./Max. Temperature, LTPD 2(116/0) Subgroup 4 A.C. LTPD 2(116/0)

COMMERICAL BURN-IN SC FLOW MIL-STD-750

1. Stabilization Bake — Method 1032, 24 Hrs. @ 150°C
2. Fine Leak 1% AQL (2) — Method 1071, Condition G or H, Maximum Leak Rate TO-3 – 5 x 10^{-7} atm cc/sec Others – 5 x 10^{-8} atm cc/sec
3. Gross Leak (2) — Method 1071, Condition C
4. Electrical Test — 100% Go/No-Go, 25°C D.C. Parameters
5. HTRB Burn-in — Method 1042, Condition A, 96 Hrs. @ 150°C
6. Electrical Test — 100% Go/No-Go 25°C D.C. Parameters
7. Group A — Subgroup 1 VIS/MEC, LTPD 5, Subgroup 2 D.C. @ 25°C LTPD 5, Subgroup 3 D.C. Min./Max. Temperature LTPD 5, Subgroup 4 A.C. LTPD 5

STANDARD PRODUCTS MIL-STD-750

1. Stabilization Bake — Method 1032, 24 Hrs. @ 150°C
2. Fine Leak 1% AQL (2) — Method 1071, Condition G or H, Maximum Leak Rate TO-3 – 5 x 10^{-7} atm cc/sec Others – 5 x 10^{-8} atm cc/sec
3. Gross Leak (2) — Method 1071, Condition C
4. Electrical Test — 100% Go/No-Go, 25°C D.C. Parameters
5. Group A — Subgroup A 0.65% AQL Subgroup 1 VIS/MEC, Subgroup 2 D.C. @ 25°C

Note 1: Processing consists of 100% screening and Group A only. Generic Group B, C, & D data available on request.
Note 2: Hermetic packages only.
Note 3: HTRGB-High temperature reverse gate bias.
Note 4: Read and Record with delta and percent values is optional.
Note 5: Optional.
Note 6: Preseal visual for SXV flow only. Not applicable for SX flow
All test methods are per MIL-STD-750 unless specified otherwise.

The following products are available with High Reliability processing per test methods and flows of MIL-STD-750 and MIL-STD-883. For ordering purposes, add the process flow prefix to the device number as shown in the following examples:

Process flow	Device Type	High Rel Part Number
SX	VN0104N2	SXVN0104N2
RB	VN0106N7	RBVN0106N7

Device Type	RB	SX	SXV	SJ	SC
2N6659		•	•	•	•
2N6660		•	•	•	•
2N6661		•	•	•	•
TN0102N2		•	•	•	•
TN0104N2		•	•	•	•
TN0106N2		•	•	•	•
TN0110N2		•	•	•	•
TN0520N2		•	•	•	•
TN0524N2		•	•	•	•
TN0602N2		•	•	•	•
TN0604N2		•	•	•	•
TN0606N2		•	•	•	•
TN0606N7	•				
TN0610N2		•	•	•	•
TN0620N2		•	•	•	•
TN0624N2		•	•	•	•
TP0102N2		•	•	•	•
TP0104N2		•	•	•	•
TP0602N2		•	•	•	•
TP0604N2		•	•	•	•
TP0606N2		•	•	•	•
TP0606N7	•				
TP0610N2		•	•	•	•
TP0616N2		•	•	•	•
TP0620N2		•	•	•	•
TQ3001N7	•				
VC0106N7	•				
VN0104N2		•	•	•	•
VN0104N7	•				
VN0104N9		•	•	•	•
VN0106N2		•	•	•	•
VN0106N7	•				
VN0106N9		•	•	•	•

Device Type	RB	SX	SXV	SJ	SC
VN0109N2		•	•	•	•
VN0109N9		•	•	•	•
VN0116N2		•	•	•	•
VN0120N2		•	•	•	•
VN0335N1		•	•	•	•
VN0335N2		•	•	•	•
VN0340N1		•	•	•	•
VN0340N2		•	•	•	•
VN0345N1		•	•	•	•
VN0345N2		•	•	•	•
VN0350N1		•	•	•	•
VN0350N2		•	•	•	•
VN0300B		Refer to TN0604N2			
VN0535N2		•	•	•	•
VN0540N2		•	•	•	•
VN0545N2		•	•	•	•
VN0550N2		•	•	•	•
VN0635N2		•	•	•	•
VN0640N2		•	•	•	•
VN0645N2		•	•	•	•
VN0650N2		•	•	•	•
VN10KN9		•	•	•	•
VN1106N2		•	•	•	•
VN1110N2		•	•	•	•
VN1116N2		•	•	•	•
VN1120N2		•	•	•	•
VN1204N2		•	•	•	•
VN1206N2		•	•	•	•
VN1210N2		•	•	•	•
VN1216N2		•	•	•	•
VN1220N2		•	•	•	•
VN1206B		Refer to TN0620N2			
VN1210B		Refer to TN0620N2			

DMOS High Reliability Products

Device type	RB	SX	SXV	SJ	SC
VN1304N2		•	•	•	•
VN1306N2		•	•	•	•
VN1310N2		•	•	•	•
VN1706B		Refer to TN0620N2			
VN1710B		Refer to TN0620N2			
VN2106NF	•				
VN2110NF	•				
VP0104N2		•	•	•	•
VP0104N7	•				
VP0104N9		•	•	•	•
VP0106N2		•	•	•	•
VP0106N7	•				
VP0106N9		•	•	•	•
VP0109N2		•	•	•	•
VP0109N9		•	•	•	•
VP0116N2		•	•	•	•
VP0120N2		•	•	•	•
VP0335N1		•	•	•	•
VP0335N2		•	•	•	•
VP0340N1		•	•	•	•
VP0340N2		•	•	•	•
VP0345N1		•	•	•	•
VP0345N2		•	•	•	•
VP0350N1		•	•	•	•
VP0350N2		•	•	•	•
VP0300B		Refer to TP0604N2			
VP0535N2		•	•	•	•

Device Type	RB	SX	SXV	SJ	SC
VP0540N2		•	•	•	•
VP0545N2		•	•	•	•
VP0550N2		•	•	•	•
VP0635N2		•	•	•	•
VP0640N2		•	•	•	•
VP0645N2		•	•	•	•
VP0650N2		•	•	•	•
VP0808B		Refer to TP0610N2			
VP1008B		Refer to TP0610N2			
VP1106N2		•	•	•	•
VP1110N2		•	•	•	•
VP1116N2		•	•	•	•
VP1120N2		•	•	•	•
VP1204N2		•	•	•	•
VP1206N2		•	•	•	•
VP1210N2		•	•	•	•
VP1216N2		•	•	•	•
VP1220N2		•	•	•	•
VP1304N2		•	•	•	•
VP1306N2		•	•	•	•
VP1310N2		•	•	•	•
VQ1000N7	•				
VQ1001P	•				
VQ1004P	•				
VQ2001P	•				
VQ2006P	•				
VQ3001N7	•				
VQ7254N7	•				

Supertex inc.

Understanding MOSFET Data

The following outline explains how to read and use Supertex MOSFET data sheets. The approach is simple and care has been taken to avoid getting lost in a maze of technical jargon.

The VN01A data sheet was chosen as an example because this is one of the most popular devices and has the largest choice of packages. The product nomenclature shown applies only to Supertex proprietary products.

Device Structure

V: Vertical DMOS (discretes & quads)

T: Low threshold vertical DMOS discretes

A: Lateral DMOS arrays

L: Lateral DMOS discretes

Type of Channel

- N-Channel, or
- P-Channel

Design

Supertex Family number

Voltage Range

Suffix	Min BV_{DSS} volts
L:	20, 40
A:	40, 60, 90, 100
C:	160, 200, 240
D:	350, 400
E:	450, 500
F:	550, 600

- Some A range devices not available in 40, 90 & 100V
- Some C range devices not available in 240V

Advanced DMOS Technology

These enhancement-mode (normally-off) DMOS FET transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and negative temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speed are desired.

This section outlines main features of the product

N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS}/ BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package						
			TO-39	TO-92	TO-52	TO-220	Quad P-DIP	Quad C-DIP	DICE
40V	3Ω	2.0A	VN0104N2	VN0104N3	VN0104N9	VN0104N5	VN0104N6	VN0104N7	VN0104ND
60V	3Ω	2.0A	VN0106N2	VN0106N3	VN0106N9	VN0106N5	VN0106N6	VN0106N7	VN0106ND
90V	3Ω	2.0A	VN0109N2	VN0109N3	VN0109N9	VN0109N5	—	—	VN0109ND

Drain to source breakdown voltage & drain to gate breakdown voltage

Maximum resistance from drain to source when device is fully turned on

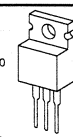
Minimum drain current when device is fully turned on

Package Options

Hermetic metal can
- Moderate power disipation
- Industrial/Military applications

Plastic
- Low power
- Mainly commerical applications
- Cost effective

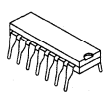
Hermetic metal can
- Low power Industrial/ Military applications



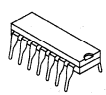
Plastic
- High power
- Commerical/Industrial applications

Ordering Information

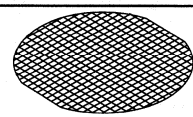
BV_{DSS}/ BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package						
			TO-39	TO-92	TO-52	TO-220	Quad P-DIP	Quad C-DIP	DICE
40V	3Ω	2.0A	VN0104N2	VN0104N3	VN0104N9	VN0104N5	VN0104N6	VN0104N7	VN0104ND
60V	3Ω	2.0A	VN0106N2	VN0106N3	VN0106N9	VN0106N5	VN0106N6	VN0106N7	VN0106ND
90V	3Ω	2.0A	VN0109N2	VN0109N3	VN0109N9	VN0109N5	—	—	VN0109ND



Dual in line plastic
- 4 dice in one package
- Commerical/Industrial applications



Dual in line ceramic
- 4 dice in one package for Industrial/Military requirements



NW: Die in wafer form
- 4 inch diameter wafers
- Reject die are inked

ND: Die in waffle pack

Die can be visually inspected to commercial (standard) or military visual criteria (specify while ordering)

Absolute Maximum Ratings

Extreme conditions a device can be subjected to electrically and thermally. Stress in excess of these ratings will usually cause permanent damage.

Ratings given in product summary.

Drain-to Source Voltage	BV_{DSS}
Drain-to-Gate	BV_{DGS}
Gate-to-Source Voltage	±20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature	300°C

V_{GS}
- Most Supertex FETs are rated fro ±20V
- ± voltage handling capability allows quick turn off by reversing bias.
- External protection should be used when there is a possibility of exceeding this rating. Stress exceeding ±20V will result in gate insulation degradation and eventual failure.

Maximum allowable temperature at leads while soldering, 1.6mm away from case for 10 seconds.

- All Supertex devices can be stored and operated satisfactorily within these junction temperature (T_J) limits.
- Appropriate derating factors from curves and change in parameters due to reduced/ elevated temperatures have to be considered when temperature is not 25°C.
- Operation at T_J below maximum limit can enhance operating life.

Thermal Characteristics

Device characteristics affecting limits of heat produced and removed from device. Die size, $R_{DS(ON)}$ and packaging type are the main factors determining these thermal limitations.

θ_{ja}

Thermal resistance from junction to air.

- Depends mainly on package and die size

θ_{jc}

Thermal resistance from junction to case.

- Depends mainly on package and die size
- To determine T_J use equation $T_J = P_D \times \theta_{jc} + T_A$

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ TC = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	0.8A	2.5A	3.5W	125	35	0.08A	2.5A
TO-92	0.5A	2.0A	1.0W	170	125	0.5A	2.0A
TO-52	0.5A	2.0A	1.0W	170	125	0.5A	2.0A
TO-220	1.5A	2.5A	15.0W	70	8	1.5A	2.5A
Plastic DIP Ceramic DIP	See DMOS Arrays & Special Functions section						

I_D (continuous)

Maximum continuous current carrying capability of device.

- Depends mainly on:
  - A. $R_{DS(ON)}$ - on state resistance
  - B. P_D - maximum power dissipation for package
  - C. Die size
  - D. Maximum junction temperature

I_D (pulsed)

Maximum non-continuous pulse current carrying capability for a 300 µS 2% duty cycle pulsed.

- Depends mainly on :
  - A. $R_{DS(ON)}$
  - B. P_D max
  - C. Diameter of bonding wire
  - D. Die size
  - E. Maximum junction temperature

Power Dissipation

- Maximum power package can dissipate when case temperature is 25°C.
- When case temperature is higher than 25°C, use P_D vs. T_C curve to determine dissipation permissible.

I_{DR}

Continuous current handling capability of drain to source diode.

- Factors affecting value same as I_D (continuous)

I_{DRM}

300 µS, 2% duty cycle pulsed. Current handling capability of drain source diode.

- Factors affecting this parameter same as I_D (pulsed)

The following DC parameters are 100% tested with 300µS, 2% duty cycle pulsed at 25°C, BV_{DSS}, $V_{GS(TH)}$, I_{DSS}, $I_{D(ON)}$ & $R_{DS(ON)}$.

- $\Delta V_{GS(TH)}$ and $\Delta R_{DS(ON)}$ are guaranteed by design ie., when device is functional for other DC parameters, these two parameters will not deviate from published values.
- Since a representative sample is adequate to assure consistency of specs, A.C. parameters are sample tested on a lot/batch basis.
- High temperature testing on sample basis when requested with hi-rel processing.
- Refer to section 3 "power MOS structures" for test circuits used for measurement.

Electrical Characteristics (@ 25°C unless otherwise specified)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN0109	90			V	V_{GS} = 0, I_D = 1mA
		VN0106	60				
		VN0104	40				
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2.4	V	V_{GS} = V_{DS}, I_D = 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.8	-5.5	mV/°C	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage			0.1	100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				1	µA	V_{GS} = 0, V_{DS} = Max Rating
					100		V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		0.5	1.0		A	V_{GS} = 5V, V_{DS} = 25V
			2.0	2.50			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			4.50	5	Ω	V_{GS} = 5V, I_D = 250mA
				2	3		V_{GS} = 10V, I_D = 1A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.70	1	%/°C	V_{GS} = 10V, I_D = 1A
G_{FS}	Forward Transconductance		300	400		m℧	V_{DS} = 25V, I_D = 0.5A
C_{ISS}	Input Capacitance			45	60	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			20	25		
C_{RSS}	Reverse Transfer Capacitance			2	5		
$t_{d(ON)}$	Turn-ON Delay Time			3	5	ns	V_{DD} = 25V, I_D = 1A, R_G = 50Ω
t_r	Rise Time			5	8		
$t_{d(OFF)}$	Turn-OFF Delay Time			6	9		
t_f	Fall Time			5	8		
V_{SD}	Diode Forward Voltage Drop			1.2	1.8	V	V_{GS} = 0, I_{SD} = 1.0A
t_{rr}	Reverse Recovery Time			400		ns	V_{GS} = 0, I_{SD} = 1A

BV_{DSS}

- Please see product summary (part I)
- Positive temperature coefficient. See curve BV_{DSS} vs. T_J.

$V_{GS(TH)}$

- Voltage required from gate to source to turn on device to certain I_D current value given in "condition" column.
- I_D measurement condition is low for small die and higher for larger die.

$\Delta V_{GS(TH)}$

- Threshold voltage reduces when temperature increases and vice versa.
- Value at temperature other than 25 °C can be determined by $V_{GS(TH)}$ (normalized) vs. T_J curve.

I_{GSS}

- Since the gate is insulated from the rest of device by a silicon dioxide insulating layer, this parameter depends on thickness/integrity of layer and size of device.
- Measured at maximum permissible voltage from gate to source: ±20V.
- Values of this parameter are often tens/hundreds of times less than published maximum value. Electrical screening is done at 100nA since test equipment functions slowly at lower values, which is not practical for mass production. Consult factory for screening lower values.

I_{DSS}

- This is the leakage current from drain to source when device is fully turned off.
- Measured by applying maximum permissible voltage between drain and source (BV_{DSS}) and gate shorted to source(V_{GS} = 0)
- Special electrical screening possible at lower values since max. published values are higher to achieve practical testing speeds.

$I_{D(ON)}$

- Defined as the minimum drain current when device is turned on.
- Supertex measures $I_{D(ON)}$ min. at two test conditions:

  V_{GS} = 5V and V_{GS} = 10V, to give the designer a look at both logic level turn on and full turn on

  Although Supertex specifies a typical value of $I_{D(ON)}$, the designer should use minimum value as the worst case.

$R_{DS(ON)}$

- Drain to source resistance measured when device is partially turned on at V_{GS} = 5V, and fully turned on at V_{GS} = 10V.
- Designers should use maximum values for worst case condition.
- When better turn on characteristics (ie., low $R_{DS(ON)}$) is required for logic level inputs, Supertex's low threshold TN & TP devices may be used.
- Typical value of $R_{DS(ON)}$ can be calculated at various V_{GS} conditions by using output characteristics or saturation characteristics family of curves (V_{GS} vs I_D).
- $R_{DS(ON)}$ increases with higher drain currents. $R_{DS(ON)}$ curve has a slight slope for low values of I_D, but rises rapidly for high values.

$\Delta R_{DS(ON)}$

- Positive temperature coefficient.
- Enhances stability due to current sharing during parallel operation.

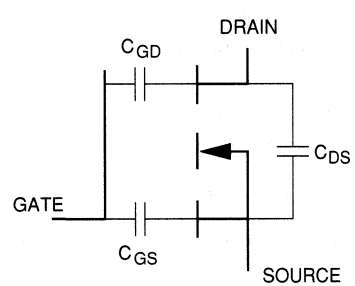
Switching Characteristics

- Extremely fast switching compared to bipolar transistors, due to absence of minority carrier storage time during turn off.
- Switching times depend almost totally on interelectrode capacitance, R_S (source impedance) and R_L (load impedance) as shown on test circuit.

C_{ISS}, C_{RSS}, C_{OSS}

- Please see section 3 in databook "Power MOSFET Electrical Performance" for interelectrode capacitances and equivalent circuit.
- Supertex interdigitated structures have lowest C_{ISS} in the industry for comparable die sizes and exhibit excellent switching characteristics.
- Values of these capacitances are high at low voltages across them. Please see capacitance vs V_{DS} curves for details.
- Negligible effect of temperature on capacitances.
- The following equation may be used for calculating effective value of C_{ISS} with "Miller Effect".

$$C_{ISS} = C_{GS} + (1+G_{FS}\, R_L)\, C_{GD}$$



$$C_{ISS} = C_{GD} + C_{GS}$$

$$C_{OSS} = C_{GD} + C_{DS}$$

$$C_{RSS} = C_{GD}$$

G_{FS}

- Represents gain of the device and can be compared to H_{FE} of a bipolar transistor.
- Value is the ratio of change in I_D for a change in V_{GS}

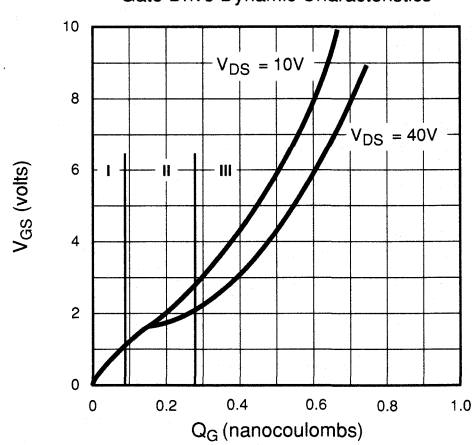
$$G_{FS} = \frac{\Delta I_D}{\Delta V_{GS}}$$

- Rises rapidly with increasing I_D, and then becomes constant in the saturation region. See V_{GS} vs. I_D curve.

$Td_{(ON)}$

During this period, the drive circuit changes C_{ISS} up to $V_{GS(TH)}$. Since no drain current flows prior to turn on, V_{DS} and consequently C_{ISS} remain constant. Region I on the V_{GS} vs. Q_G curve shows linear change in voltage with increasing Q_G.

Gate Drive Dynamic Characteristics



Electrical Characteristics (@ 25°C unless otherwise specified)

(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN0109	90			V	V_{GS} = 0, I_D = 1mA
		VN0106	60				
		VN0104	40				
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2.4	V	V_{GS} = V_{DS}, I_D = 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.8	-5.5	mV/°C	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage			0.1	100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				1	μA	V_{GS} = 0, V_{DS} = Max Rating
					100		V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		0.5	1.0		A	V_{GS} = 5V, V_{DS} = 25V
			2.0	2.50			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			4.50	5	Ω	V_{GS} = 5V, I_D = 250mA
				2	3		V_{GS} = 10V, I_D = 1A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.70	1	%/°C	V_{GS} = 10V, I_D = 1A
G_{FS}	Forward Transconductance		300	400		m℧	V_{DS} = 25V, I_D = 0.5A
C_{ISS}	Input Capacitance			45	60	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			20	25		
C_{RSS}	Reverse Transfer Capacitance			2	5		
$t_{d(ON)}$	Turn-ON Delay Time			3	5	ns	V_{DD} = 25V I_D = 1A R_S = 50Ω
t_r	Rise Time			5	8		
$t_{d(OFF)}$	Turn-OFF Delay Time			6	9		
t_f	Fall Time			5	8		
V_{SD}	Diode Forward Voltage Drop			1.2	1.8	V	V_{GS} = 0, I_{SD} =1.0A
t_{rr}	Reverse Recovery Time			400		ns	V_{GS} = 0, I_{SD} = 1A

t_r

- When C_{ISS} is driven to a voltage exceeding $V_{GS(TH)}$, conduction from drain source begins. G_{FS} increases causing increase in C_{ISS} due to "Miller Effect" Charge requirements to Region II increase considerably. Gain stabilizes in Region III and "Miller Effect" is nullified, resulting in a linear change in V_{GS} for increase in Q_G.

$t_{d(OFF)}$

- The sequence of events now begins to reverse. C_{ISS} discharges through R_S and the 50Ω resistor. The rise of V_{DS} is initially slowed by increase of output capacitance.

t_f

- V_{DS} rises rapidly as the output capacitance falls.

V_{SD}

- This is the forward voltage drop of the parasitic diode between drain and source.
- Diode my be used as a commutator in H bridge configurations or in a synchronous rectifier mode. Excessive fly back voltages may be clamped by this diode in a totem pole configuration.

t_{RR}

- The reverse recovery time is the time needed for the carrier gradient, formed during forward biasing, to be depleted when the biasing is reversed.
- An external fast recovery diode may be connected from drain to source to improve recovery time.

DMOS Products

Supertex DMOS MOSFET family utilizes both vertical and lateral, double-diffused MOS processes. These DMOS MOSFETs are ideally suited for a wide range of switching, driving, and amplifying applications. They feature high input impedance, fast switching speeds, and low threshold voltages. Available in a wide variety of packages types, they give the designer flexibility using state-of-the-art semiconductor technology.

N-Channel Low Threshold MOSFETs

Device Family	BV_{DSS} Min(V)	$RDS_{(ON)}$ Max (ohms)	$I_{D(ON)}$ Min(A)	C_{ISS} Typ(pf)	$V_{GS(ON)}$ Max(V)	Package Options					
						TO-39	TO-92	TO-220	SOT89	Quad[1]	Die
TN01L	20, 40	1.8	2.0	45	1.6	•	•		•		•
TN01A	60, 100	3.0	2.0	50	1.6	•	•				•
TN05C	200, 240	10.0	0.3	45	1.5	•	•				•
TN05D	350, 400	22.0	0.25	48	2.0		•				•
TN06L	20, 40	0.75	4.0	100	1.6	•	•				•
TN06A	60, 100	1.50	3.0	100	1.6	•	•	•		•	•
TN06C	200, 240	6.0	1.0	110	1.6	•	•	•		•	•
TN06D	350, 400	10.0	1.0	105	1.8		•				•
TN07L	20	1.3	0.5	130	1.0		•				•
TN25L	20, 40	1.0	4.0	100	1.6				•		•
TN25A	60, 100	1.5	3.0	100	1.6				•		•
TN25C	200, 240	6.0	1.0	110	2.0				•		•
TN25D	350, 400	12.0	1.0	105	1.8				•		•

Note:1. Refer to Arrays and Special Functions section for packages available.

P-Channel Low Threshold MOSFETs

Device Family	BV_{DSS} Min(V)	$RDS_{(ON)}$ Max (ohms)	$I_{D(ON)}$ Min(A)	C_{ISS} Typ(pf)	$V_{GS(ON)}$ Max(V)	Package Options					
						TO-39	TO-92	TO-220	SOT89	Quad[1]	Die
TP01L	20, 40	4.0	0.85	45	2.4	•	•		•		•
TP06L	20, 40	2.0	2.0	100	2.4	•	•			•	•
TP06A	60, 100	3.5	1.5	100	2.4	•	•	•		•	•
TP06C	160, 200	12.0	0.75	100	2.4	•	•	•			•
TP07L	20	3.0	0.35	130	1.4		•				•
TP25L	20, 40	2.0	2.0	100	2.4				•		•
TP25A	60, 100	3.5	1.5	100	2.4				•		•
TP25C	160, 200	12.0	0.75	110	2.4				•		•
TP25D	350, 400	25.0	0.4	100	2.4		•		•		•

Note: 1. Refer to Arrays and Special Functions section for packages available.

N-Channel DMOS Power FETs

Device Family	BV_{DSS} Min(V)	$RDS_{(ON)}$ Max (ohms)	$I_{D(ON)}$ Min(A)	C_{ISS} Typ(pf)	Package Options						
					TO-3	TO-39	TO-52	TO-92	TO-220	Quad[1]	Die
VN01A	40, 60, 90	3.0	2.0	45		•	•	•	•	•	•
VN01C	160, 200	10.0	0.4	45		•		•	•		•
VN03D	350, 400	2.5	3.0	550	•	•			•		•
VN03E	450, 500	4.0	2.0	550	•	•			•		•
VN03F	550, 600	6.0	1.5	550	•				•		•
VN05D	350, 400	35.0	0.25	45		•		•			•
VN05E	450, 500	60.0	0.15	45		•		•			•
VN06D	350, 400	10.0	0.75	105		•		•	•		•
VN06E	450, 500	16.0	.50	125		•		•	•		•
VN06F	550, 600	20.0	0.25	85		•		•	•		•
VN11A	60, 100	0.7	8.0	240		•			•		•
VN11C	160, 200	3.0	2.0	280		•			•		•
VN12A	40, 60, 100	0.3	20.0	700		•			•		•
VN12C	160, 200	1.0	6.0	775		•			•		•
VN13A	40, 60, 100	8.0	0.50	25		•		•			
VN21A	60, 100	3.0	0.5	45						•	•
VN22A	40, 60, 100	0.35	8.0	400				•			•

Note: 1. Refer to Arrays and Special Functions section for packages available.

P-Channel DMOS Power FETs

Device Family	BV_{DSS} Min(V)	$RDS_{(ON)}$ Max (ohms)	$I_{D(ON)}$ Min(A)	C_{ISS} Typ(pf)	Package Options						
					TO-3	TO-39	TO-52	TO-92	TO-220	Quad[1]	Die
VP01A	40, 60, 90	8.0	0.50	45		•	•	•	•	•	•
VP01C	160, 200	25.0	0.35	50		•		•	•		•
VP03D	350, 400	6.0	1.5	600	•	•			•		•
VP03E	450, 500	7.5	1.0	500	•	•			•		•
VP05D	350, 400	75.0	0.20	45		•		•			•
VP05E	450, 500	125.0	0.10	45		•		•			•
VP06D	350, 400	25.0	0.40	105		•		•	•		•
VP06E	450, 500	25.0	0.20	95		•		•	•		•
VP11A	60, 100	2.0	5.0	300		•			•		•
VP11C	160, 200	5.0	1.5	300		•			•		•
VP12A	40, 60, 100	0.8	6.0	550		•			•		•
VP12C	160, 200	2.5	4.0	600		•			•		•
VP13A	40, 60, 100	25.0	0.25	25		•		•		•	
VP22A	40, 60, 100	0.9	4.0	450				•			•

Note: 1. Refer to Arrays and Special Functions section for packages available.

Supertex inc.

DMOS Power FETS

The following table represents an industry cross–reference for power MOSFETs. The Supertex devices are a "form, fit, and function" replacement for the industry standard part types, but subtle differences in charateriestics and/or specifications may exist.

Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number
2N6659	2N6659	2SK382	VN0350N5	BSS250	VP0106N3	D84BM2	VN1216N5
2N6660	2N6660	2SK383	VN1210N5	BSS295	VN2206N3	D84BN2	VN1220N5
2N6661	2N6661	2SK402	VN0340N1	BSS296	VN2210N3	D84BQ1	VN0335N5
2N6759	VN0335N1	2SK408	TN0620N5	BSS297	TN0620N3	D84BQ2	VN0340N5
2N6761	VN0345N1	2SK409	TN0620N5	BSS87	TN2524N8	D84CK2	VN1206N5
2N6781	VN1106N2	2SK411	VN0360N1	BSS88	TN0624N3	D84CL2	VN1210N5
2N6782	VN1110N2	2SK428	VN1206N5	BSS89	TN0620N3	D84CM2	VN1216N5
2N7000	2N7000	2SK440	VN1220N5	BSS92	TP0620N3	D84CN2	VN1220N5
2N7007	2N7007	2SK441	VN0650N2	BSS98	VN0106N3	D84CQ1	VN0335N5
2N7008	2N7008	2SK680	TN0104N8	BST120	TP0104N8	D84CQ2	VN0340N5
2N7009	VN0550N3	AM0610LL	TN0624N3	BST122	TP0104N8	D84CR1	VN0345N5
2N7010	VN2206N3	AM10LM	VN0106N3	BST70A	VN0109N3	D84CR2	VN0350N5
2N7011	VN2206N3	AM2222LL	VN0106N3	BST72	VN1310N3	D84DK2	VN1206N5
2N7014	VN1110N5	AM2222LM	VN0106N3	BST72A	VN1310N2	D84DL2	VN1210N5
2SJ101	VP1204N5	AN0110NA	AN0116NA	BST74	TN0620N3	IRF320	VN0340N1
2SJ102	VP1206N5	AN0120NA	AN0120NA	BST74A	TN0620N3	IRF321	VN0335N1
2SJ117	VP0340N5	AN0130NA	AN0130NA	BST76	TN0620N3	IRF322	VN0340N1
2SJ121	VP1204N5	AN0140NA	AN0140NA	BST76A	TN0620N3	IRF323	VN0335N1
2SJ76	VP0116N5	AP0120NA	AP0120NA	BST84	TN2524N8	IRF332	VN0340N1
2SJ77	TP0616N5	AP0130NA	AP0130NA	BST86	TN2524N8	IRF333	VN0335N1
2SJ78	VP1220N5	AP0140NA	AP0140NA	BUZ20	VN1210N5	IRF420	VN0350N1
2SJ79	VP0120N5	BS107	VN0120N3	BUZ30	VN1220N5	IRF421	VN0345N1
2SJ79K	VP0120N5	BS107P	VN0120N3	BUZ40	VN0350N5	IRF422	VN0350N1
2SK196H	VN0116N2	BS107PT	VN1320N3	BUZ42	VN0350N5	IRF423	VN0345N1
2SK213	TN0620N5	BS170	VN0106N3	BUZ43	VN0350N1	IRF432	VN0350N1
2SK214	TN0620N5	BS170P	VN0106N3	BUZ46	VN0350N1	IRF433	VN0345N1
2SK215	TN0620N5	BS229	TN0624N3	BUZ60B	VN0340N5	IRF510	VN1210N5
2SK216	TN0620N5	BS250	VP0106N3	BUZ63B	VN0340N1	IRF511	VN1206N5
2SK216K	TN0620N5	BS250P	VP0106N3	BUZ72	VN1210N5	IRF512	VN1210N5
2SK259	VN0335N1	BSR78	TP0604N3	BUZ72A	VN1210N5	IRF513	VN1206N5
2SK260	VN0340N1	BSS100	TN0610N3	BUZ73A	VN1220N5	IRF520	VN1210N5
2SK294	VN1210N5	BSS101	TN0524N3	BUZ74	VN0350N5	IRF521	VN1206N5
2SK295	VN1210N5	BSS11O	VP0106N3	BUZ74A	VN0350N5	IRF522	VN1210N5
2SK296	VN0335N5	BSS124	TN0640N3	BUZ76	VN0340N5	IRF523	VN1206N5
2SK298	VN0340N1	BSS125	VN0660N3	BUZ76A	VN0340N5	IRF530	VN1210N5
2SK302	TN0104N8	BSS129	TN0624N3	D80AK2	TN0606N3	IRF531	VN1206N5
2SK310	VN0340N5	BSS135	VN0660N3	D80AL2	TN0610N3	IRF532	VN1210N5
2SK311	VN0345N5	BSS149	TN0624N3	D80AM2	TN0620N3	IRF533	VN1206N5
2SK319	VN0340N5	BSS192	TP2520N8	D80AN2	TN0620N3	IRF610	VN1220N5
2SK345	VN1204N5	BSS192	TP2520N8	D84BK2	VN1206N5	IRF611	VN1216N5
2SK346	VN1206N5	BSS229	TN0624N3	D84BL2	VN1210N5	IRF612	VN1120N5

Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number
IRF613	VN1216N5	IRFF220	VN1220N2	IVN6000CNE	VN1206N5	MFE500	VN0550N2
IRF620	VN1220N5	IRFF221	VN1216N2	IVN6000CNF	VN1210N5	MFE910	VN10KN9
IRF621	VN1216N5	IRFF222	VN1220N2	IVN6000CNH	TN0610N5	MFE9200	VN2406L
IRF622	VN1220N5	IRFF223	VN1216N2	IVN6000CNR	VN0340N5	MFE930	TN0604N2
IRF623	VN1216N5	IRFF232	VN1220N2	IVN6000CNS	VN0340N5	MFE960	TN0606N2
IRF632	VN1220N5	IRFF233	VN1216N2	IVN6000CNT	VN0345N5	MFE990	TN0610N2
IRF633	VN1216N5	IRFF310	VN0340N2	IVN6000CNU	VN0350N5	MFQ1000C	TN0606N7
IRF710	VN0340N5	IRFF311	VN0335N2	IVN6000KNR	VN0340N1	MFQ170P	TN0606N6
IRF711	VN0335N5	IRFF312	VN0340N2	IVN6000KNS	VN0340N1	MFQ6660C	TN0606N7
IRF712	VN0340N5	IRFF313	VN0335N2	IVN6000KNT	VN0345N1	MFQ6660P	TN0606N6
IRF713	VN0335N5	IRFF320	VN0340N2	IVN6000KNU	VN0350N1	MFQ6661P	VQ1006J
IRF720	VN0340N5	IRFF321	VN0335N2	IVN6000TNE	TN0606N2	MPF480	VN1310N3
IRF721	VN0335N5	IRFF322	VN0340N2	IVN6000TNF	TN0610N2	MPF481	VN1310N3
IRF722	VN0340N5	IRFF323	VN0335N2	IVN6000TNH	TN0610N2	MPF500	VN0550N3
IRF723	VN0335N5	IRFF332	VN0340N2	IVN6000TNR	VN0340N2	MPF6659	TN0604N3
IRF732	VN0340N5	IRFF333	VN0335N2	IVN6000TNS	VN0340N2	MPF6660	TN0606N3
IRF733	VN0335N5	IRFF420	VN0350N2	IVN6000TNT	VN0345N2	MPF6661	TN0610N3
IRF820	VN0350N5	IRFF421	VN0345N2	IVN6000TNU	VN0350N2	MPF910	VN0106N3
IRF821	VN0345N5	IRFF422	VN0350N2	IVN6001CNE	VN1206N5	MPF9200	TN0620N3
IRF822	VN0350N5	IRFF423	VN0345N2	IVN6001CNF	VN1210N5	MPF930	TN0604N3
IRF823	VN0345N5	IRFG9113	TP0606N7	IVN6001CNH	TN0610N5	MPF960	TN0606N3
IRF832	VN0350N5	IRFS1Z0	TN2524N8	IVN6001TNE	VN1206N2	MPF990	TN0610N3
IRF833	VN0345N5	IRFS1Z3	TN0104N8	IVN6001TNF	VN1210N2	MTM2N45	VN0345N1
IRF9510	VP1210N5	IVN5000AND	TN0104N3	IVN6001TNH	VN1210N2	MTM2N50	VN0350N1
IRF9511	VP1206N5	IVN5000AND	TN0104N3	IVN6002CND	VN1204N5	MTM2P45	VP0345N1
IRF9512	VP1210N5	IVN5000ANE	TN0606N3	IVN6002TND	TN0104N2	MTM2P50	VP0350N1
IRF9513	VP1206N5	IVN5000ANF	TN0610N3	IVN6100TNS	VN0640N2	MTM3N35	VN0335N1
IRF9520	VP1210N5	IVN5000ANH	TN0610N3	IVN6100TNT	VN0645N2	MTM3N40	VN0340N1
IRF9521	VP1206N5	IVN5000ANH	TN0610N3	IVN6100TNU	VN0650N2	MTP10N05	VN1206N5
IRF9522	VP1210N5	IVN5000SND	VN0104N9	IVN6200ANE	VN1206N5	MTP10N06	VN1206N5
IRF9523	VP1206N5	IVN5000SNE	VN0106N9	IVN6200ANF	VN1210N5	MTP10N08	VN1210N5
IRF9532	VP1210N5	IVN5000SNF	VN0109N9	IVN6200ANH	VN1210N5	MTP10N10	VN1210N5
IRF9533	VP1206N5	IVN5000SNF	VN0109N9	IVN6200ANM	VN1220N5	MTP12N05	VN1206N5
IRF9610	VP1220N5	IVN5000SNH	VN0109N9	IVN6200ANS	VN0340N5	MTP12N06	VN1206N5
IRF9611	VP1216N5	IVN5000TND	TN0104N2	IVN6200CND	VN1204N5	MTP12N08	VN1210N5
IRF9612	VP1120N5	IVN5000TND	TN0104N2	IVN6200CNE	VN1206N5	MTP12N10	VN1210N5
IRF9613	VP1116N5	IVN5000TNE	TN0606N2	IVN6200CNF	VN1210N5	MTP15N05	VN1206N5
IRF9620	VP1220N5	IVN5000TNF	TN0610N2	IVN6200CNH	VN1210N5	MTP15N06	VN1206N5
IRF9621	VP1216N5	IVN5000TNH	TN0610N2	IVN6200CNM	VN1220N5	MTP1N45	VN0645N5
IRF9622	VP1220N5	IVN5000TNH	TN0610N2	IVN6200CNR	VN0340N5	MTP1N50	VN0350N5
IRF9623	VP1216N5	IVN5200HND	VN1204N5	IVN6200CNS	VN0340N5	MTP1N55	VN0355N5
IRF9632	VP1220N5	IVN5200HNE	VN1206N5	IVN6200CNU	VN0350N5	MTP1N60	VN0360N5
IRF9633	VP1216N5	IVN5200HNF	VN1210N5	IVN6200KNR	VN0340N1	MTP20N08	VN1210N5
IRFF110	VN1210N2	IVN5200HNH	VN1210N5	IVN6200KNS	VN0340N1	MTP20N10	VN1210N5
IRFF111	VN1206N2	IVN5200KND	VN1204N5	IVN6200KNU	VN0350N1	MTP2N18	VN1220N5
IRFF112	VN1110N2	IVN5200KNE	VN1206N5	IVN6300ANE	VN1306N3	MTP2N20	VN1220N5
IRFF113	VN1106N2	IVN5200KNF	VN1210N5	IVN6300ANF	VN1310N3	MTP2N35	VN0335N5
IRFF120	VN1210N2	IVN5200KNH	VN1210N5	IVN6300ANH	TN0610N3	MTP2N40	VN0340N5
IRFF121	VN1206N2	IVN5200TND	VN1204N2	IVN6300ANM	VN1320N3	MTP2N45	VN0345N5
IRFF122	VN1210N2	IVN5200TNE	VN1206N2	IVN6300ANP	VN0635N3	MTP2N50	VN0350N5
IRFF123	VN1206N2	IVN5200TNH	VN1210N2	IVN6300ANS	VN0540N3	MTP2P45	VN0345N5
IRFF130	VN1210N2	IVN5201CND	VN1204N5	IVN6300ANT	VN0545N3	MTP2P50	VN0350N5
IRFF131	VN1206N2	IVN5201CNE	VN1206N5	IVN6300ANU	VN0545N3	MTP3N12	VN1216N5
IRFF132	VN1210N2	IVN5210CNF	VN1210N5	IVN6300SNE	VN0106N9	MTP3N15	VN1216N5
IRFF133	VN1210N2	IVN5210CNH	VN1210N5	IVN6300SNF	VN0109N9	MTP3N35	VN0335N1
IRFF210	VN1220N2	IVN5210TND	VN1204N2	IVN6300SNH	VN0109N9	MTP3N40	VN0340N5
IRFF211	VN1216N2	IVN5210TNE	VN1206N2	IVN6660	VN0106N2	MTP4N08	VN1110N5
IRFF212	VN1120N2	IVN5210TNF	VN1210N2	IVN6661	VN0109N2	MTP4N10	VN1110N5
IRFF213	VN1216N2	IVN5210TNH	VN1210N2	MFE350	VN0535N2	MTP5N05	VN1106N5

Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number
MTP5N06	VN1206N5	RFL2N05	VN1106N2	SD1114BD	VN0109N3	UFNF433	VN0345N2
MTP5N18	VN1220N5	RFL2N06	VN1106N2	SD1114DD	VN0109N9	VN01000D	VN1210N5
MTP7N12	VN1216N5	RFM3N45	VN0345N1	SD1114HD	VN0109N2	VN0104N3	VN0104N3
MTP7N15	VN1216N5	RFM3N50	VN0350N1	SD1115BD	VN0109N3	VN0104ND	VN0104ND
MTP7N18	VN1220N5	RFM4N35	VN0335N1	SD1115DD	VN0109N9	VN0106N3	VN0106N3
MTP7N20	VN1220N5	RFM4N40	VN0340N1	SD1115HD	VN0109N2	VN0106ND	VN0106ND
MTP8N08	VN1210N5	RFP12N08	VN1210N5	SD1117BD	TN0606N3	VN0109N3	VN0109N3
MTP8N10	VN1210N5	RFP12N10	VN1210N5	SD1117DD	VN0106N9	VN0109ND	VN0109ND
MTP8N12	VN1216N5	RFP15N05	VN1206N5	SD1117HD	TN0606N2	VN0300D	VN0300D
MTP8N15	VN1216N5	RFP15N06	VN1206N5	SD1117N	VQ1001J	VN0300L	VN0300L
MTP8P08	VP1210N5	RFP1N35	VN0635N5	SD1122BD	TN0520N3	VN0300M	VN0300L
MTP8P10	VP1210N5	RFP1N40	VN0640N5	SD1122CHP	TN0520ND	VN0401D	VN1204N5
MXF350	TN2524N8	RFP2N08	TN0610N5	SD1124BD	VN0106N3	VN0601D	VN1206N5
MXF500	TN2524N8	RFP2N10	VN1110N5	SD1127BD	VN0106N3	VN0606M	VN0606LL
MXF930	TN0104N8	RFP2N12	VN1216N5	SD1127CHP	VN0106ND	VN0610L	VN0610LL
MXF960	TN0104N8	RFP2N15	VN1216N5	SD1137BD	TN0606N3	VN0610LL	VN0610LL
MXF990	TN2524N8	RFP2N18	VN1120N5	SD1137CHP	TN0606ND	VN0801D	VN1210N5
PM1001L	TN0610N3	RFP2N20	VN1120N5	SD1200CHP	VN0545ND	VN0808M	VN0808L
PM1002L	TN0610N3	RFP2P08	TP0610N5	SD1201BD	VN0540N3	VN10KE	VN0106N9
PM1003P	VN1110N5	RFP2P10	TP0610N5	SD1201CHP	VN0540ND	VN10KM	VN10KN3
PM1004P	VN1110N5	RFP3N45	VN0345N5	SD1202BD	TN0520N3	VN10KMA	VN10KN3
PM1006P	VN1210N5	RFP3N50	VN0350N5	SD1202CHP	TN0520ND	VN10KN3	VN10KN3
PM1010P	VN1210N5	RFP4N05	VN1106N5	SD1500BD	VN0660N3	VN10LE	VN0106N9
PM1201L	TN0620N3	RFP4N06	VN1106N5	SD1500CHP	VN0660ND	VN10LM	VN10KN3
PM1203P	VN1216N5	RFP4N35	VN0335N5	SD1501BD	VN0655N3	VN10LM	VN10KN3
PM1206P	VN1216N5	RFP4N40	VN0340N5	SD1501CHP	VN0660ND	VN10LP	VN1306N3
PM1503P	VN1216N5	RFP6P08	VP1210N5	SD204CHP	VN2106ND	VN1206B	VN1206B
PM1504P	VN1216N5	RFP6P10	VP1210N5	SD204HD	VN0104N3	VN1206D	VN1206D
PM1506P	VN1216N5	RFP8N18	VN1220N5	SD2107BD	VP0109N3	VN1206L	VN1206L
PM503L	TN0606N3	RFP8N20	VN1220N5	SD2107CHP	TP0610ND	VN1206M	VN1206L
PM506L	TN0606N3	RFP8P08	VP1210N5	SD2107DD	VP0109N9	VN1210L	VN1210L
PM509P	VN1206N5	RFP8P10	VP1210N5	SD2107HD	TP0610N2	VN1210M	VN1210L
PM510P	VN1206N5	SD1100CHP	VN0545ND	SD2204BD	VP0540N3	VN1216B	VN1216N2
PM512P	VN1206N5	SD1100HD	VN0545N2	SD2204CHP	VP0540ND	VN1706B	VN1706B
PM601L	VN0106N3	SD1101BD	VN0640N3	SD3300BD	VN2210N3	VN1706D	VN1706D
PM602L	TN0606N3	SD1101CHP	VN0540ND	SD3300CHP	VN2210ND	VN1706L	VN1706L
PM603L	TN0606N3	SD1101HD	VN0640N2	SD3300HD	TN0610N2	VN1706M	VN1706L
PM604P	VN1106N5	SD1102BD	VN0635N3	SD3301BD	TN0604N3	VN1710L	VN1710L
PM605P	VN1206N5	SD1102CHP	VN0635ND	SD3301CHP	VN2206ND	VN1710M	VN1710L
PM606L	TN0606N3	SD1102HD	VN0635N2	SD3301HD	TN0604N2	VN2010L	VN2010L
PM608P	VN1206N5	SD1104BD	TN0610N3	SD5101N	VN1304N6	VN2222KM	VN2222LL
PM609P	VN1206N5	SD1104DD	VN0109N9	SGSP531	VN0340N1	VN2222L	VN2222LL
PM609R	VN1206N5	SD1104HD	TN0610N2	SN0120NA	AN0120NA	VN2222LL	VN2222LL
PM610P	VN1206N5	SD1105BD	TN0610N3	SN0120NB	AN0120NB	VN2222LM	VN2222LL
PM612P	VN1206N5	SD1105DD	VN0109N9	SN0130NA	AN0130NA	VN2222LM	VN1306N3
PM614P	VN1206N5	SD1105HD	TN0610N2	SN0130NB	AN0130NB	VN2406B	VN2406B
PM801L	VN0109N3	SD1106AD	VN0106N3	SN0140NA	AN0140NA	VN2406D	VN2406D
PM802L	TN0610N3	SD1106CHP	VN0106ND	SN0140NB	AN0140NB	VN2406L	VN2406L
PM805P	VN1210N5	SD1106DD	VN0106N9	SN7000	2N7000	VN2406M	VN2406L
PM808P	VN1210N5	SD1107BD	TN0110N3	SP0610L	VP0106N3	VN2410L	VN2410L
PM814P	VN1210N5	SD1107CHP	TN0110ND	TN0106N3	TN0106N3	VN2410M	VN2410L
RFL1N08	TN0610N2	SD1107DD	VN0109N9	TN0106ND	TN0106ND	VN30ABA	VN0104N2
RFL1N10	TN0610N2	SD1107HD	TN0110N2	TN0110N3	TN0110N3	VN3501A	VN0335N1
RFL1N12	VN1216N2	SD1107N	VQ1000N6	TN0110ND	TN0110ND	VN3501D	VN0335N5
RFL1N15	VN1216N2	SD1112BD	TN0620N3	TZ400BD	VN0104N3	VN3515L	VN3515L
RFL1N18	VN1120N2	SD1112HD	TN0620N2	TZ402BD	VN1304N3	VN35AB	TN0606N2
RFL1N20	VN1120N2	SD1113BD	TN0520N3	TZ403BD	VN1304N3	VN35AK	TN0606N2
RFL1P08	TP0610N2	SD1113CHP	TN0520ND	TZ404BD	VN1304N3	VN4001A	VN0340N1
RFL1P10	TP0610N2	SD1113HD	TN0520N2	TZ404CY	TN0104N8	VN4001D	VN0340N5

Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number
VN4012L	VN4012L	VQ2000P	VQ2006P	ZVN0216M	VN0216N1	ZVN1135L	VN0335N5
VN40AD	VN0104N5	VQ2001J	TP0604N6	ZVN0220B	TN0620N2	ZVN1135M	VN0335N1
VN4502A	VN0345N1	VQ2001P	VQ2001P	ZVN0220L	TN0620N5	ZVN1140B	VN0340N2
VN4502D	VN0345N5	VQ2004J	TP0606N6	ZVN02A2B	TN0602N2	ZVN1140L	VN0340N5
VN46AD	VN0104N5	VQ2004P	VQ2006P	ZVN02A2L	VN0300D	ZVN1140M	VN0340N1
VN5002A	VN0350N1	VQ2006J	TP0606N6	ZVN02A3B	TN0604N2	ZVN1145B	VN0345N2
VN5002D	VN0350N5	VQ2006P	VQ2006P	ZVN02A3L	VN0300D	ZVN1145L	VN0345N5
VN6035L	VN6035L	VQ3001J	VQ3001N6	ZVN0330B	VN0335N2	ZVN1145M	VN0345N1
VN66AD	VN0106N5	VQ3001P	VQ3001N7	ZVN0330L	VN0335N5	ZVN11A2B	VN1204N2
VN66AK	VN0106N2	VQ7254J	VQ7254N6	ZVN0330M	VN0335N1	ZVN11A2L	VN1204N5
VN67AA	VN0106N5	VQ7254P	VQ7254N7	ZVN0335B	VN0335N2	ZVN11A3B	VN1204N2
VN67AB	VN0106N2	ZVN0104A	VN0104N3	ZVN0335L	VN0335N5	ZVN11A3L	VN1204N5
VN67ABA	VN0106N2	ZVN0104B	VN0104N2	ZVN0335M	VN0335N1	ZVN1204B	VN1204N2
VN67AD	VN0106N5	ZVN0104L	VN0104N5	ZVN0340B	VN0340N2	ZVN1204L	VN1204N5
VN67AK	VN0106N2	ZVN0106A	VN0106N3	ZVN0340L	VN0340N5	ZVN1206B	VN1206N2
VN88AD	VN0109N5	ZVN0106B	VN0106N2	ZVN0340M	VN0340N1	ZVN1206L	VN1206N5
VN89ABA	VN0109N2	ZVN0106L	VN0106N5	ZVN0345B	VN0345N2	ZVN1208B	VN1210N2
VN89AD	VN0109N5	ZVN0108A	VN0109N3	ZVN0345L	VN0345N5	ZVN1208L	VN1210N5
VN90AB	VN0109N2	ZVN0108B	VN0109N2	ZVN0345M	VN0345N1	ZVN1209B	VN1210N2
VN90ABA	VN0109N2	ZVN0108L	VN0109N5	ZVN0350L	VN0350N5	ZVN1209L	VN1210N5
VN98AK	VN0109N2	ZVN0109A	VN0109N3	ZVN0350M	VN0350N1	ZVN1210B	VN1110N2
VN99AB	VN0109N2	ZVN0109A	VN0109N3	ZVN0355B	VN0355N2	ZVN1210L	VN1110N5
VN99AK	VN0109N2	ZVN0109B	VN0109N2	ZVN0355L	VN0355N5	ZVN1214B	VN1216N2
VNC010B	VN1206N2	ZVN0109L	VN0109N5	ZVN0355M	VN0355N1	ZVN1214L	VN1216N5
VNC011B	VN1206N2	ZVN0110A	VN1310N3	ZVN0360B	VN0360N2	ZVN1216L	VN1216N5
VND010B	VN1210N2	ZVN0110B	VN1310N2	ZVN0360L	VN0360N5	ZVN1220B	VN1220N2
VND011B	VN1210N2	ZVN0110L	TN0610N5	ZVN0360M	VN0360N1	ZVN1220L	VN1220N5
VNE010B	VN1210N2	ZVN0114A	TN0620N3	ZVN0450M	VN0350N1	ZVN12A2B	VN1204N2
VNE011B	VN1210N2	ZVN0114B	TN0620N2	ZVN0530A	VN0535N3	ZVN12A3B	VN1204N2
VP0104N3	VP0104N3	ZVN0114L	TN0620N5	ZVN0530B	VN0535N2	ZVN12A3L	VN1204N5
VP0104ND	VP0104ND	ZVN0116A	VN0116N3	ZVN0535A	VN0535N3	ZVN1304A	VN1304N3
VP0106N3	VP0106N3	ZVN0116B	VN0116N2	ZVN0535B	VN0635N2	ZVN1304B	VN1304N2
VP0106ND	VP0106ND	ZVN0116L	VN0115N5	ZVN0535L	VN0635N5	ZVN1306A	VN1306N3
VP0109N3	VP0109N3	ZVN0117TA	VN0120N3	ZVN0540A	VN0540N3	ZVN1306B	VN1306N2
VP0109ND	VP0109ND	ZVN0120A	VN0120N3	ZVN0540B	VN0540N2	ZVN1308A	VN1310N3
VP0300B	VP0300B	ZVN0120B	VN0120N2	ZVN0540L	VN0640N5	ZVN1308B	VN1310N2
VP0300L	VP0300L	ZVN0120L	VN0120N5	ZVN0545A	VN0545N3	ZVN1309A	VN1310N3
VP0300M	VP030OL	ZVN0124A	TN0524N3	ZVN0545B	VN0545N2	ZVN1309B	VN1310N2
VP0535N3	VP0535N3	ZVN0124B	TN0524N2	ZVN0545L	VN0645N5	ZVN1310A	VN1310N3
VP0535ND	VP0109ND	ZVN0124L	TN0624N5	ZVN1104B	TN0604N2	ZVN1310B	VN1310N2
VP0535ND	VP0535ND	ZVN01A2A	TN0102N3	ZVN1104L	VN1106N5	ZVN1314A	VN0116N3
VP0540L	VP0640N5	ZVN01A2B	TN0602N2	ZVN1106B	VN1106N2	ZVN1314B	VN0116N2
VP0540N3	VP0540N3	ZVN01A2L	VN0300D	ZVN1106L	VN1106N5	ZVN1316A	VN1316N3
VP0540ND	VP0540ND	ZVN01A3B	TN0604N2	ZVN1108B	VN1110N2	ZVN1316B	VN1316N2
VP0610L	VP0106N3	ZVN01A3L	TN0606N5	ZVN1108L	VN1110N5	ZVN1320A	VN1320N3
VP0614L	VP0106N3	ZVN0204B	TN0104N2	ZVN1109B	VN1110N2	ZVN1320B	VN1320N2
VP0808B	VP0808B	ZVN0204L	TN0606N5	ZVN1109L	VN1110N5	ZVN1404A	VN1304N3
VP0808L	VP0808L	ZVN0206B	TN0606N2	ZVN1110B	TN0610N2	ZVN1404B	VN1304N2
VP0808M	VP0808L	ZVN0206L	TN0606N5	ZVN1110L	TN0610N5	ZVN1406A	VN1306N3
VP1008B	TP0610N2	ZVN0208B	TN0610N2	ZVN1114B	VN1216N2	ZVN1406B	VN1306N2
VP1008L	VP1008L	ZVN0208L	TN0610N5	ZVN1114L	VN1216N5	ZVN1408A	VN1310N3
VP1008M	TP0610N3	ZVN0209B	TN0610N2	ZVN1116B	VN1116N2	ZVN1408B	VN1310N2
VQ1000J	VQ1000N6	ZVN0209L	TN0610N5	ZVN1116L	TN0620N5	ZVN1409A	VN1310N3
VQ1000P	VQ1000N7	ZVN0210B	TN0610N2	ZVN1120B	VN1120N2	ZVN1409B	VN1310N2
VQ1001J	TN0606N6	ZVN0210L	TN0610N5	ZVN1120L	VN1120N5	ZVN1410A	VN1310N3
VQ1001P	VQ1001P	ZVN0214B	TN0620N2	ZVN1130B	VN0335N2	ZVN1410B	VN1310N2
VQ1004J	VQ1004J	ZVN0214L	VN1216N5	ZVN1130L	VN0335N5	ZVN1414A	VN1316N3
VQ1004P	VQ1004P	ZVN0216B	TN0620N2	ZVN1130M	VN0335N1	ZVN1414B	VN1316N2
VQ2000J	TP0606N6	ZVN0216L	TN0620N5	ZVN1135B	VN0335N2	ZVN1416A	VN1316N3

Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number	Industry Part Number	Supertex Part Number
ZVN1416B	VN1316N2	ZVN2535B	VN0535N2	ZVP0109A	VP0109N3	ZVP0545L	VP0645N5
ZVN1420A	VN0120N3	ZVN2535L	VN0535N5	ZVP0109B	VP0109N2	ZVP1320A	VP1320N3
ZVN1420B	VN0120N2	ZVN3210L	VN1210N5	ZVP0109L	VP0109N5	ZVP1320B	VP1320N2
ZVN2106A	TN0606N3	ZVN3220L	VN1220N5	ZVP0110A	VP0109N3	ZVP2106A	TP0606N3
ZVN2106B	TN0606N2	ZVN3306A	VN0106N3	ZVP0110B	VP0109N2	ZVP2106B	TP0606N2
ZVN2106L	TN0606N5	ZVN3306B	VN0106N2	ZVP0110L	VP0109N5	ZVP2106L	TP0606N5
ZVN2110A	TN0610N3	ZVN3310A	VN1310N3	ZVP0120A	VP0120N3	ZVP2110A	VP0109N3
ZVN2110B	TN0610N2	ZVN3310B	VN1310N2	ZVP0120B	VP0120N2	ZVP2110B	VP0109N2
ZVN2110L	TN0610N5	ZVN3320A	VN1320N3	ZVP0120L	VP0120N5	ZVP2110L	TP0610N5
ZVN2120A	VN0120N3	ZVN3320B	VN1320N3	ZVP0204A	TP0606N3	ZVP2120A	VP0120N3
ZVN2120B	VN0120N2	ZVN4206A	TN0606N3	ZVP0204B	TP0606N2	ZVP2120B	VP0120N2
ZVN2120CSM	TN2524N8	ZVNL120A	VN0120N3	ZVP0206A	TP0606N3	ZVP2120L	VP0120N5
ZVN2120L	VN0120N5	ZVNL535A	VN0535N3	ZVP0206B	TP0606N2	ZVP2206B	VP1206N2
ZVN2206B	VN1206N2	ZVP0104A	VP0104N3	ZVP0208A	TP0610N3	ZVP2206L	VP1206N5
ZVN2206L	VN1206N5	ZVP0104B	VP0104N2	ZVP0208B	TP0610N2	ZVP2210B	VP1110N2
ZVN2210B	VN1110N2	ZVP0104L	VP0104N5	ZVP0535A	VP0535N3	ZVP2210L	VP1110N5
ZVN2210L	VN1110N5	ZVP0106A	VP0106N3	ZVP0535B	VP0535N2	ZVP2220B	TP0620N2
ZVN2220B	VN1120N2	ZVP0106B	VP0106N2	ZVP0535L	VP0635N5	ZVP2220L	TP0620N5
ZVN2220L	VN1120N5	ZVP0106L	VP0106N5	ZVP0540A	VP0540N3	ZVP3306A	VP0106N3
ZVN2224B	TN0624N2	ZVP0108A	VP0109N3	ZVP0540B	VP0540N2	ZVP3306B	VP0106N2
ZVN2224L	TN0624N5	ZVP0108B	VP0109N2	ZVP0545A	VP0545N3	ZVP3310A	VP1310N3
ZVN2535A	VN0535N3	ZVP0108L	VP0109N5	ZVP0545B	VP0545N2	ZVP3310B	VP1310N2

N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package		
				TO-39	TO-92	DICE†
60V	3Ω	2A	1.6V	TN0106N2	TN0106N3	TN0106ND
100V	3Ω	2A	1.6V	TN0110N2	TN0110N3	TN0110ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Low threshold — 1.6V max.
- ☐ High input impedance
- ☐ Low input capacitance — 50 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

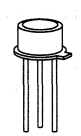
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

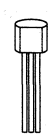
These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-39



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	0.5A	2.0A	1.0W	170	125	1.0A	4.0A
TO-92	0.8A	2.5A	3.5W	125	35	2.5A	5.0A

* I_D (continuous) is limited by max rated T_j.

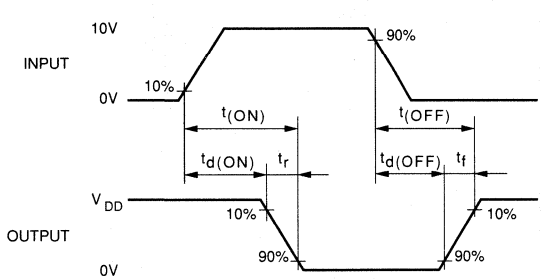
Electrical Characteristics (@ 25°C unless otherwise specified)

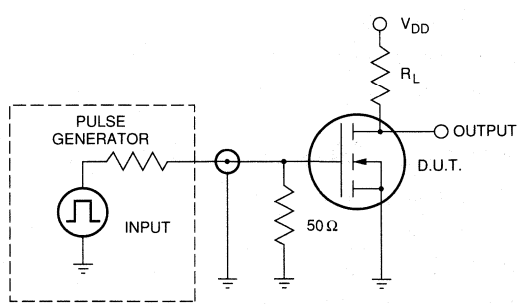
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TN0110	100			V	I_D = 1mA, V_{GS} = 0
		TN0106	60				
$V_{GS(th)}$	Gate Threshold Voltage		0.6		1.6	V	V_{GS} = V_{DS}, I_D = 0.5mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.2	-5.0	mV/°C	V_{GS} = V_{DS}, I_D = 1.0mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					500		V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		0.75	1.4		A	V_{GS} = 5V, V_{DS} = 25V
			2.0	3.4			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			2.5	4.5	Ω	V_{GS} = 5V, I_D = 250mA
				2.0	3.0		V_{GS} = 10V, I_D = 500mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.6	1.1	%/°C	I_D = 0.5A, V_{GS} = 10V
G_{FS}	Forward Transconductance		225	400		m℧	V_{DS} = 25V, I_D = 500mA
C_{ISS}	Input Capacitance			50	60	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			25	35		
C_{RSS}	Reverse Transfer Capacitance			4	8		
$t_{d(ON)}$	Turn-ON Delay Time			2	5	ns	V_{DD} = 25V, I_D = 1.0A, R_S = 50Ω
t_r	Rise Time			3	5		
$t_{d(OFF)}$	Turn-OFF Delay Time			6	7		
t_f	Fall Time			3	5		
V_{SD}	Diode Forward Voltage Drop			1	1.5	V	I_{SD} = 0.5A, V_{GS} = 0
t_{rr}	Reverse Recovery Time			400		ns	I_{SD} = 0.5A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

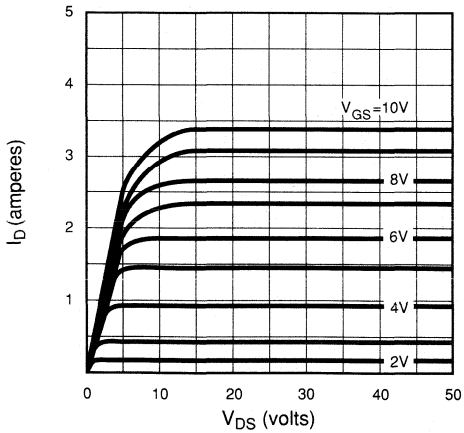
Switching Waveforms and Test Circuit



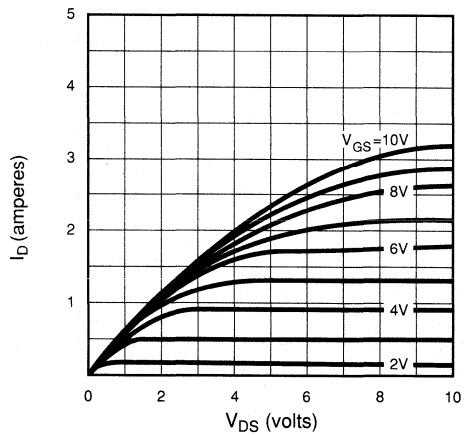


Typical Performance Curves

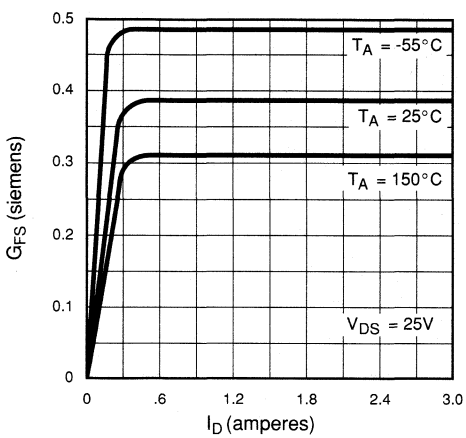
Output Characteristics



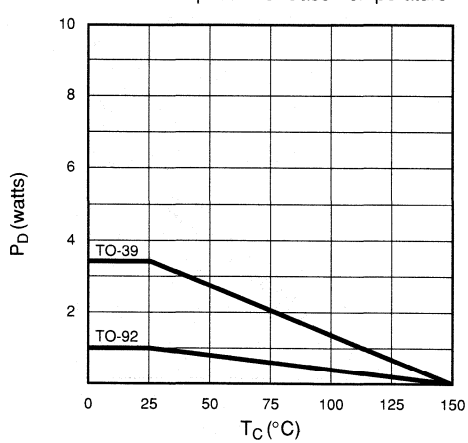
Saturation Characteristics



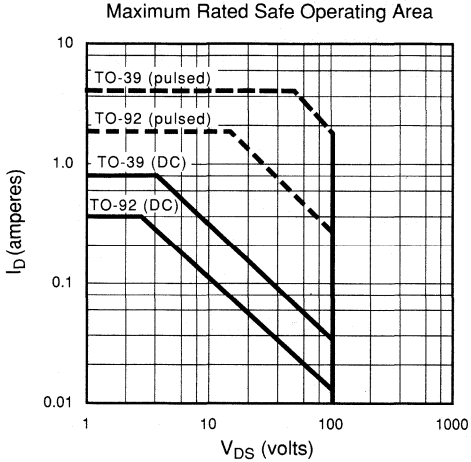
Transconductance vs. Drain Current



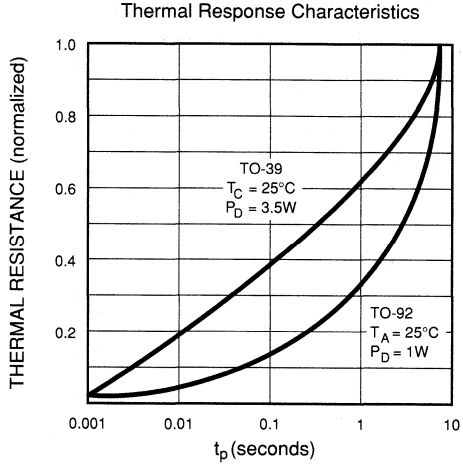
Power Dissipation vs. Case Temperature



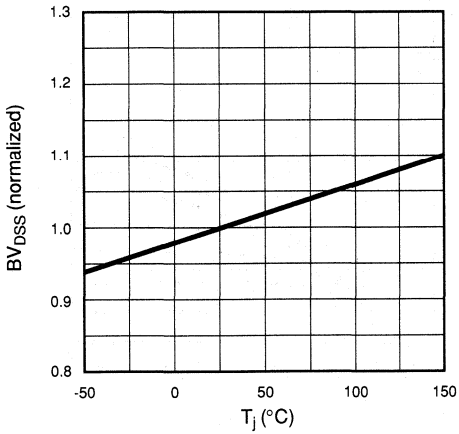
Maximum Rated Safe Operating Area



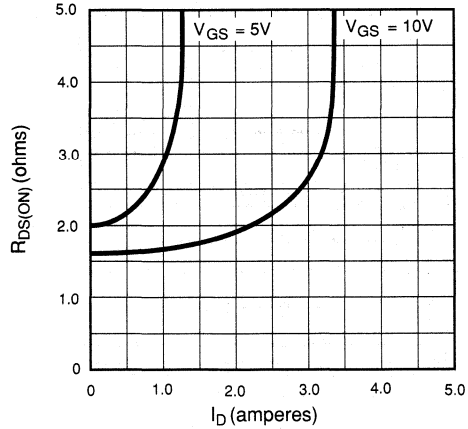
Thermal Response Characteristics



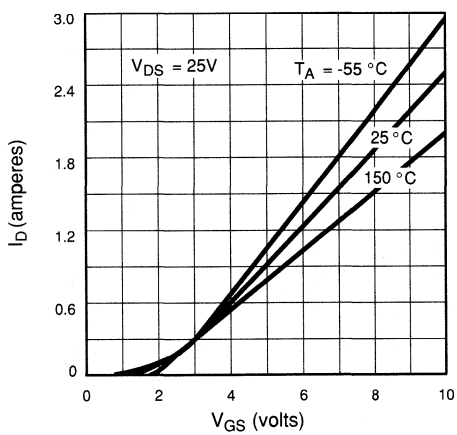
BV$_{DSS}$ Variation with Temperature



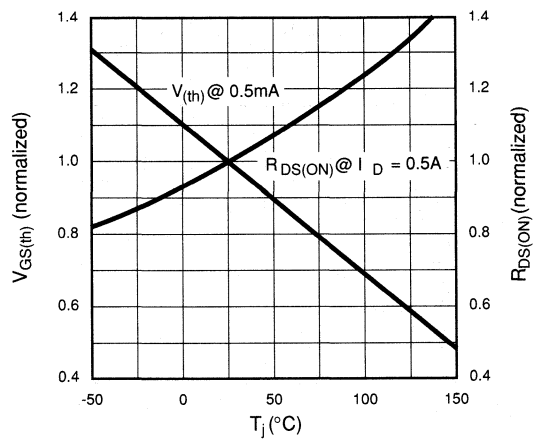
On-Resistance vs. Drain Current



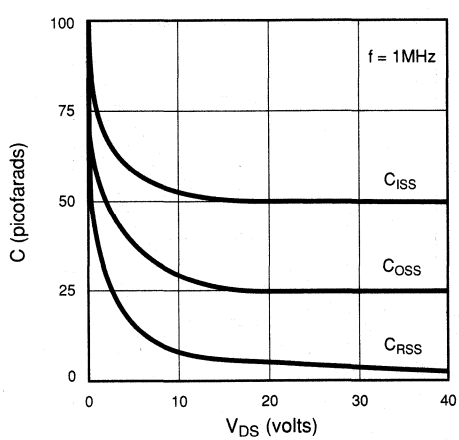
Transfer Characteristics



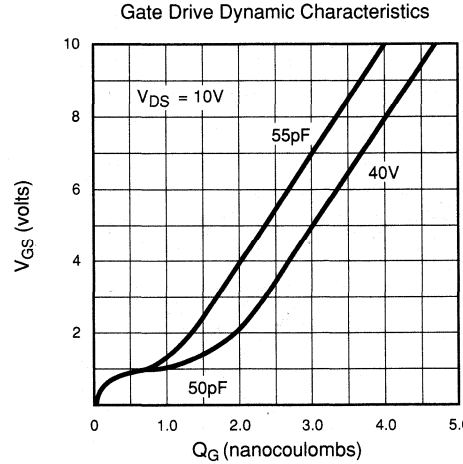
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$V_{GS(th)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package			
				TO-39	TO-92	TO-243AA*	DICE†
20V	1.8Ω	1.6V	2.0A	TN0102N2	TN0102N3	—	TN0102ND
40V	1.8Ω	1.6V	2.0A	TN0104N2	TN0104N3	—	TN0104ND
40V	2.0Ω	1.6V	2.0A	—	—	TN0104N8	—

* Same as SOT-89.
† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Low threshold —1.6V max.
- ☐ High input impedance
- ☐ Low input capacitance — 52 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

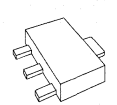
* For TO-39 and TO-92, distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

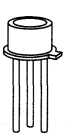
These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

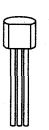
Package Options (Note 1)



TO-243AA
(SOT-89)



TO-39



TO-92

Note 1: See package outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-39	1.25A	2.90A	3.5W	35	125	1.25A	2.90A
TO-92	0.80A	2.40A	1.0W	125	170	0.80A	2.40A
TO-243AA	0.42A	2.20A	0.55W†	–	–	0.42A	2.20A

* I_D (continuous) is limited by max rated T_j.
† Mounted on FR5 Board, 25mm x 19mm x 1.57mm. Signficant P_D increase possible on ceramic substrate.

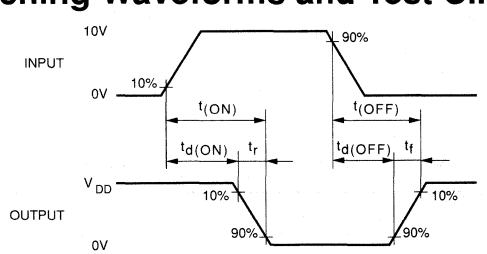
Electrical Characteristics (@ 25°C unless otherwise specified)

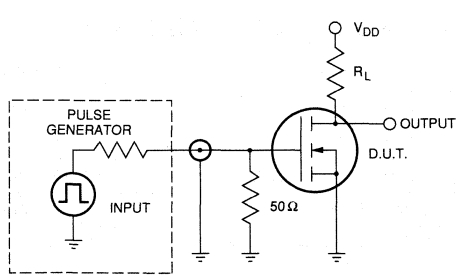
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TN0104	40			V	V_{GS}= 0, I_D = 1.0mA
		TN0102	20				
$V_{GS(th)}$	Gate Threshold Voltage		0.6		1.6	V	V_{GS} = V_{DS}, I_D = 500µA
$V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.8	-5.0	mV/°C	V_{GS} = V_{DS}, I_D = 1.0mA
I_{GSS}	Gate Body Leakage			0.1	100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				1	µA	V_{GS} =0, V_{DS} = Max Rating
					100	µA	V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			0.35		A	V_{GS} = 3V, V_{DS} = 25V
			0.5	1.1			V_{GS} = 5V, V_{DS} = 25V
			2.0	2.6			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	All Packages		5.0		Ω	V_{GS} = 3V, I_D = 50mA
				2.3	2.5		V_{GS} = 5V, I_D = 250mA
		TO-39, TO-92		1.5	1.8		V_{GS} = 10V, I_D = 1A
		TO-243AA			2.0		V_{GS} = 10V, I_D = 1A
$\Delta R_{DS(ON)}$	Change in RDS(ON) with Temperature			0.7	1.0	%/°C	V_{GS} =10V, I_D = 1A,
G_{FS}	Forward Transconductance		0.34	0.45		℧	V_{DS} = 25V, I_D = 0.5A
C_{ISS}	Input Capacitance			52	60	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			21	25		
C_{RSS}	Reverse Transfer Capacitance			2	5		
$t_{d(ON)}$	Turn-ON Delay Time			3	5	ns	V_{DD} = 25V, I_D = 1A R_S = 50Ω
t_r	Rise Time			7	8		
$t_{d(OFF)}$	Turn-OFF Delay Time			6	9		
t_f	Fall Time			5	8		
V_{SD}	Diode Forward Voltage Drop	TO-39, TO-92		1.2	1.8	V	V_{GS} = 0, I_{SD} = 1.0A
		TO-243AA			2.0		V_{GS} = 0, I_{SD} = 0.5A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

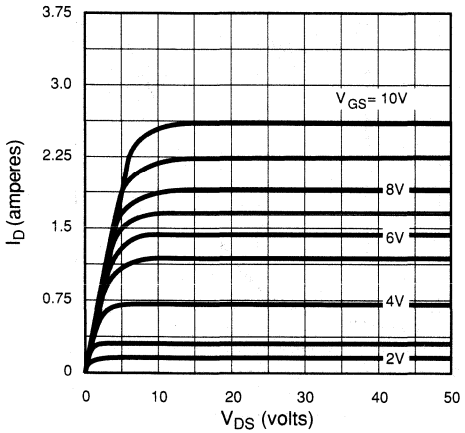
Switching Waveforms and Test Circuit



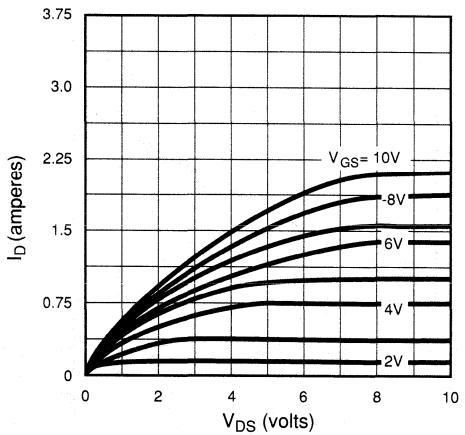


Typical Performance Curves

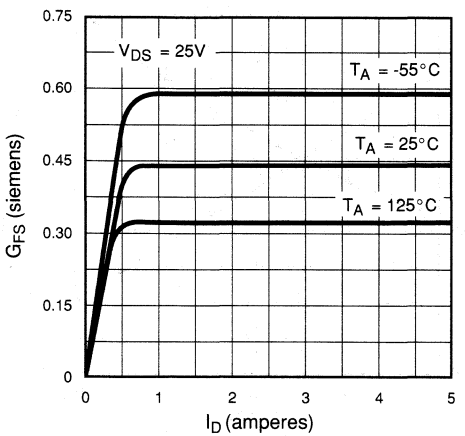
Output Characteristics



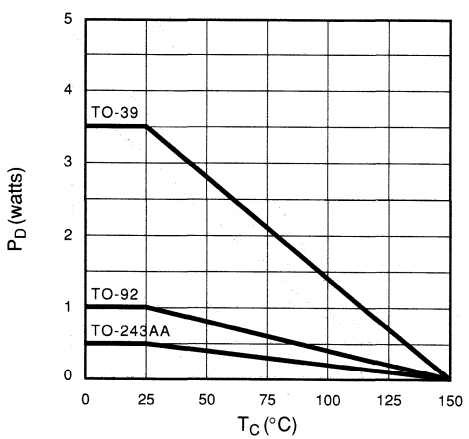
Saturation Characteristics



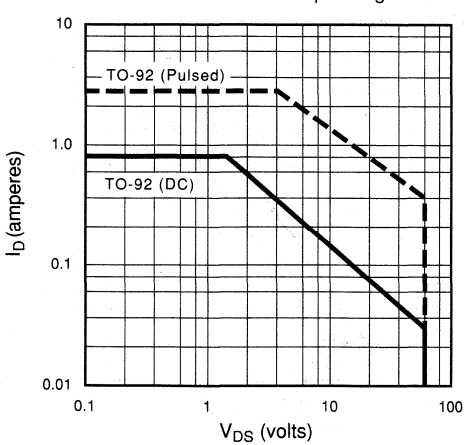
Transconductance vs. Drain Current



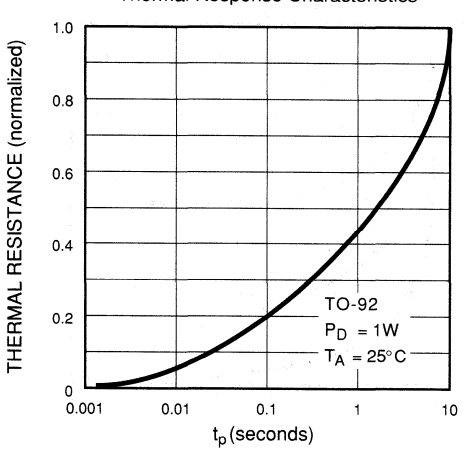
Power Dissipation vs. Case Temperature



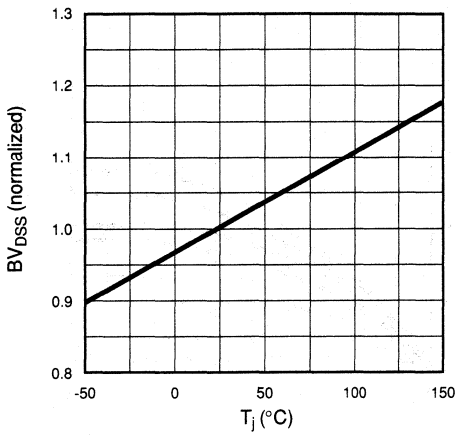
Maximum Rated Safe Operating Area



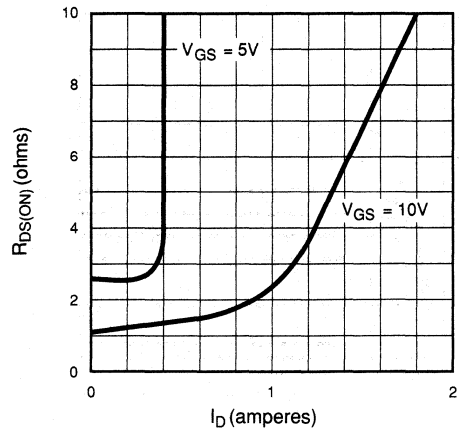
Thermal Response Characteristics



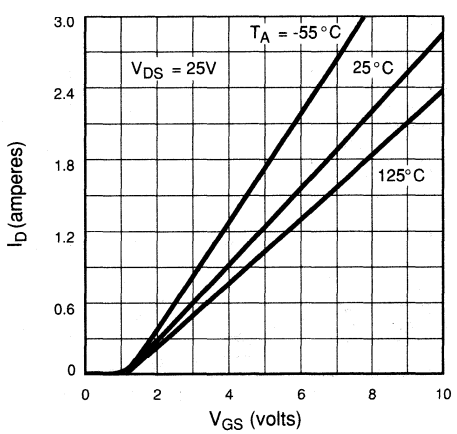
BV$_{DSS}$ Variation with Temperature



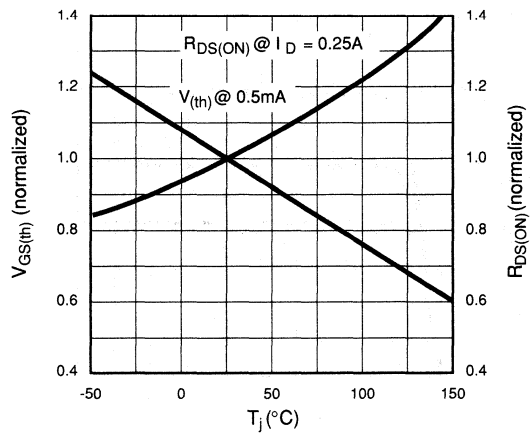
On-Resistance vs. Drain Current



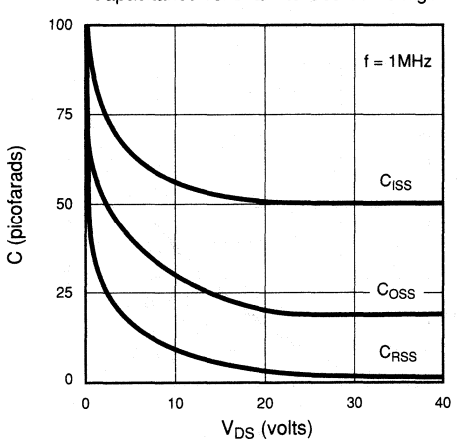
Transfer Characteristics



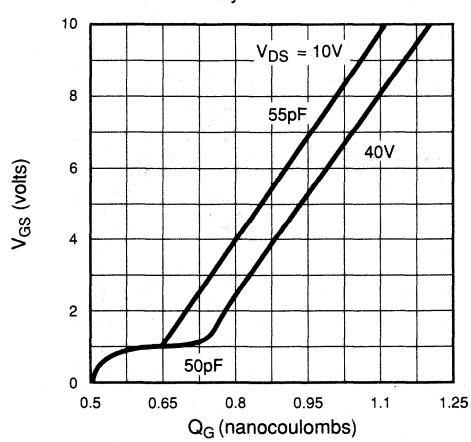
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package		
				TO-39	TO-92	DICE†
200V	10Ω	300mA	1.5V	TN0520N2	TN0520N3	TN0520ND
240V	10Ω	300mA	1.5V	TN0524N2	TN0524N3	TN0524ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Low threshold —1.5V max.
- ☐ High input impedance
- ☐ Low input capacitance — 45 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

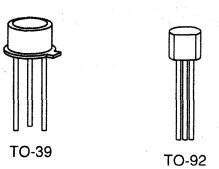
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-39	0.7A	1.5A	3.5W	35	125	0.7A	1.5A
TO-92	0.3A	1.0A	1.0W	125	170	0.3A	1.0A

* I_D (continuous) is limited by max rated T_j.

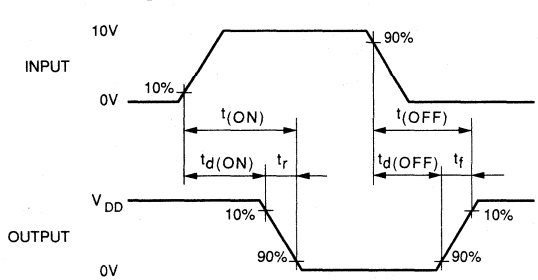
Electrical Characteristics (@ 25°C unless otherwise specified)

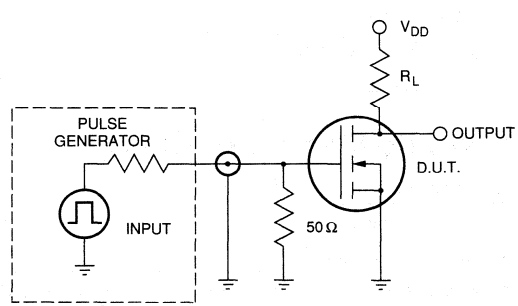
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TN0524	240			V	V_{GS}= 0, I_D =1mA
		TN0520	200				
$V_{GS(th)}$	Gate Threshold Voltage		0.6		1.5	V	V_{GS} = V_{DS}, I_D = 1.0mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.0	-4.0	mV/°C	V_{GS} = V_{DS}, I_D = 1.0mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					500		V_{DS} = 0, V_{GS} = 0.8 Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		100	360		mA	V_{GS} = 3V, V_{DS} = 25V
			300	850			V_{GS} = 5V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			9	15	Ω	V_{GS} = 3V, I_D = 50mA
				7	10		V_{GS} = 5V, I_D = 100mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.9	1.5	%/°C	V_{GS} = 5V, I_D = 0.2A
G_{FS}	Forward Transconductance		0.15	0.35		℧	V_{DS} = 25V, I_D = 0.2A
C_{ISS}	Input Capacitance			45	60	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			15	35		
C_{RSS}	Reverse Transfer Capacitance			3	8		
$t_{d(ON)}$	Turn-ON Delay Time			3	5	ns	V_{DD} = 25V I_D = 0.2A R_S = 50Ω
t_r	Rise Time			3	5		
$t_{d(OFF)}$	Turn-OFF Delay Time			5	7		
t_f	Fall Time			3	5		
V_{SD}	Diode Forward Voltage Drop			1.1	2.5	V	V_{GS} = 0, I_{SD} = 100mA
t_{rr}	Reverse Recovery Time			400		ns	V_{GS} = 0, I_{SD} = 100mA

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

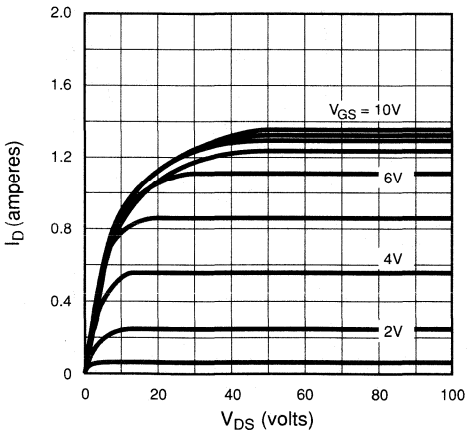
Switching Waveforms and Test Circuit



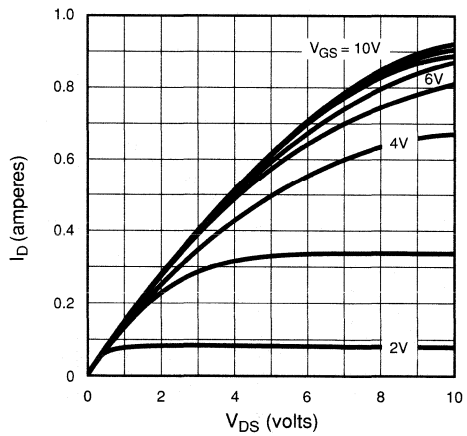


Typical Performance Curves

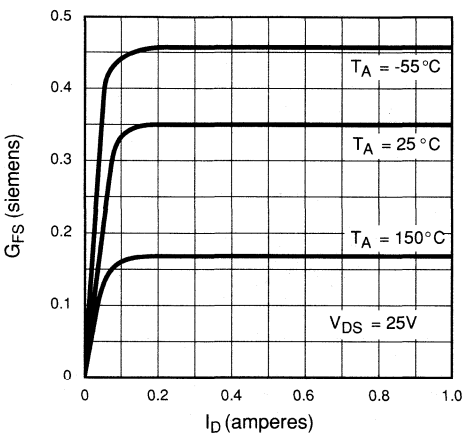
Output Characteristics



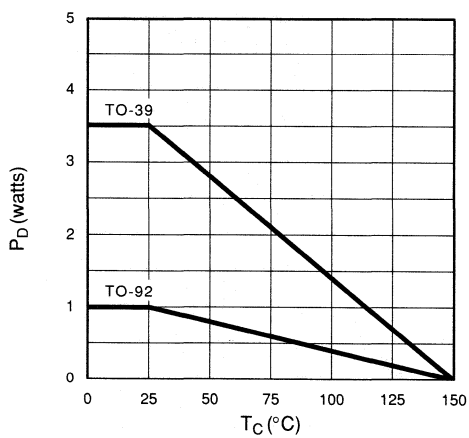
Saturation Characteristics



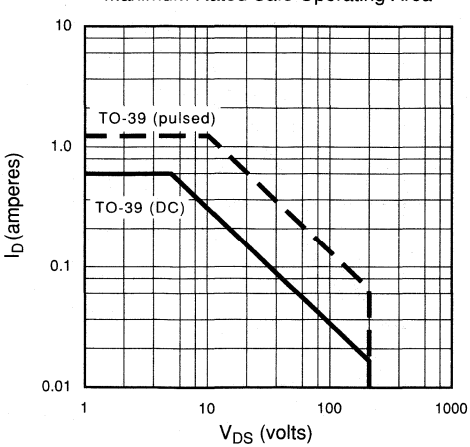
Transconductance vs. Drain Current



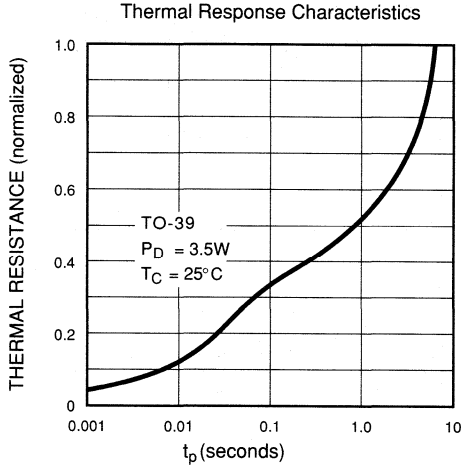
Power Dissipation vs. Case Temperature



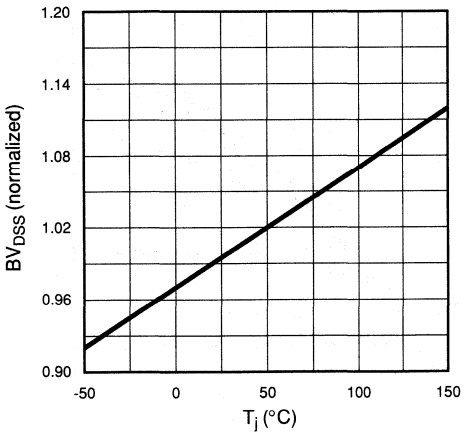
Maximum Rated Safe Operating Area



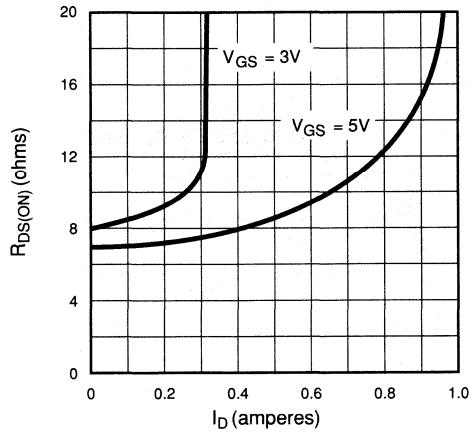
Thermal Response Characteristics



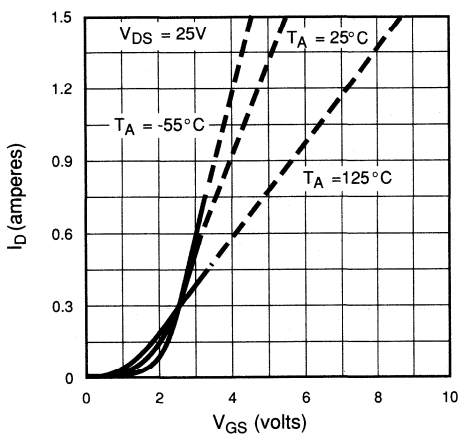
BV$_{DSS}$ Variation with Temperature



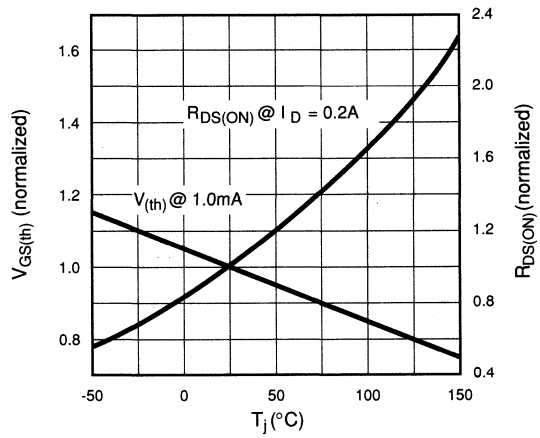
On-Resistance vs. Drain Current



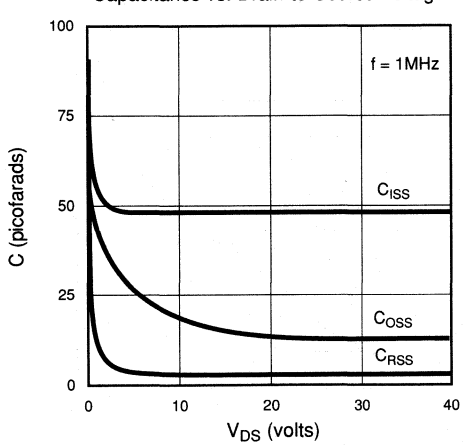
Transfer Characteristics



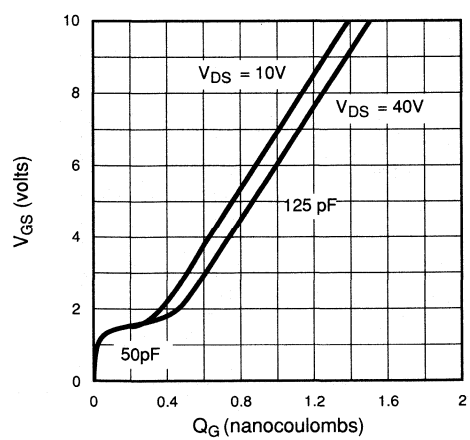
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package	
				TO-92	DICE†
350V	22Ω	250mA	2.0V	TN0535N3	TN0535ND
400V	22Ω	250mA	2.0V	TN0540N3	TN0540ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Low threshold —2.0V max.
- ☐ High input impedance
- ☐ Low input capacitance — 48 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

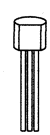
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-92	140mA	750mA	1.0W	170	125	140mA	750mA

* I_D (continuous) is limited by max rated T_j.

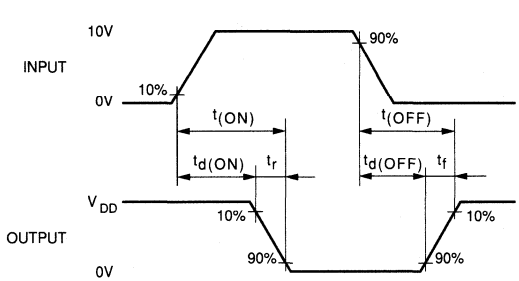
Electrical Characteristics (@ 25°C unless otherwise specified)

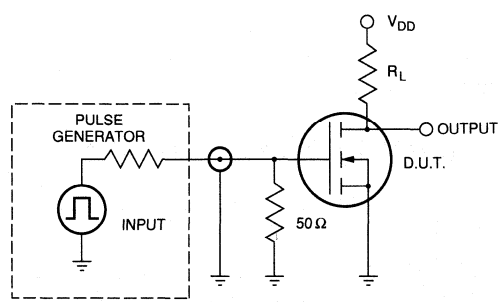
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TN0540	400			V	V_{GS} = 0, I_D = 1mA
		TN0535	350				
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2.0	V	V_{GS} = V_{DS}, I_D= 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.5	-4.5	mV/°C	
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					500	µA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			550		mA	V_{GS} = 5V, V_{DS} = 25V
			250	750			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			20	22	Ω	V_{GS} = 4.5V, I_D = 100mA
				19	22		V_{GS} = 10V, I_D = 150mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.9	1.5	%/°C	V_{GS} = 10V, I_D = 0.1A
G_{FS}	Forward Transconductance		125	200		m℧	V_{DS} = 25V, I_D = 0.1A
C_{ISS}	Input Capacitance			48	60	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			11	15		
C_{RSS}	Reverse Transfer Capacitance			3	8		
$t_{d(ON)}$	Turn-ON Delay Time			5	8	ns	V_{DD} = 25V, I_D = 150mA, R_S = 50Ω
t_r	Rise Time			5	8		
$t_{d(OFF)}$	Turn-OFF Delay Time			5	8		
t_f	Fall Time			5	8		
V_{SD}	Diode Forward Voltage Drop			0.8	1.2	V	V_{GS} = 0, I_{SD} = 150mA
t_{rr}	Reverse Recovery Time			400		ns	V_{GS} = 0, I_{SD} = 150mA

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

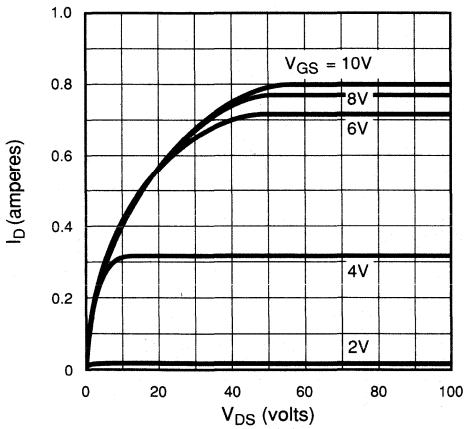
Switching Waveforms and Test Circuit



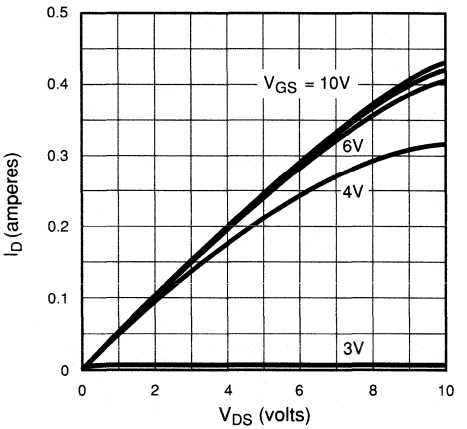


Typical Performance Curves

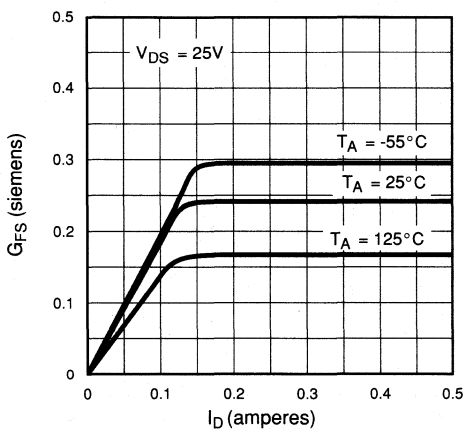
Output Characteristics



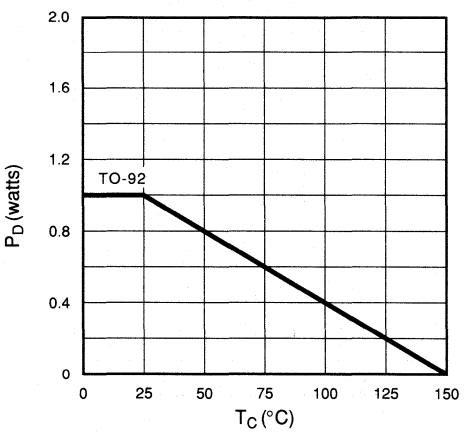
Saturation Characteristics



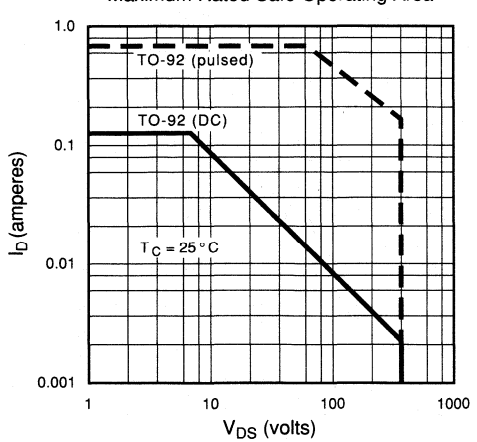
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

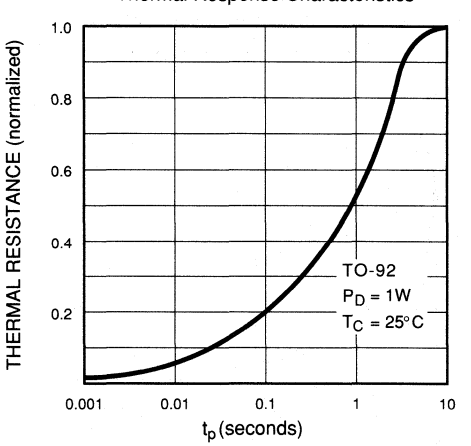


Maximum Rated Safe Operating Area

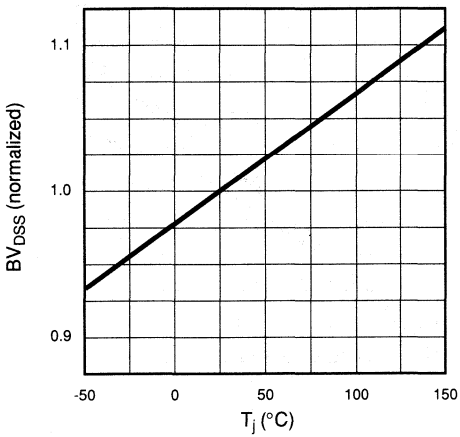


Pulsed Condition: 300µs, 2% dutycycle

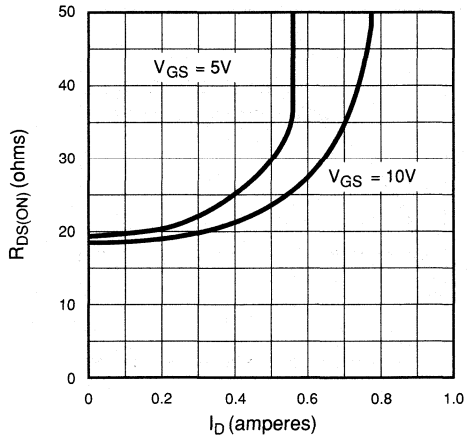
Thermal Response Characteristics



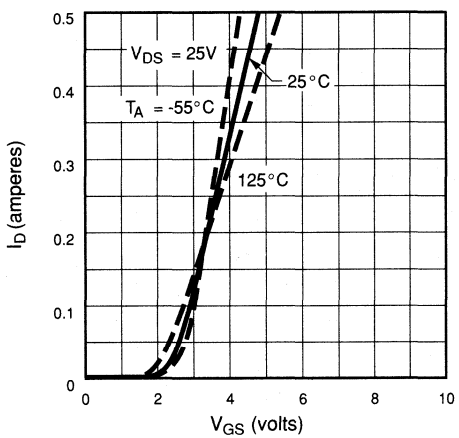
BV_{DSS} Variation with Temperature



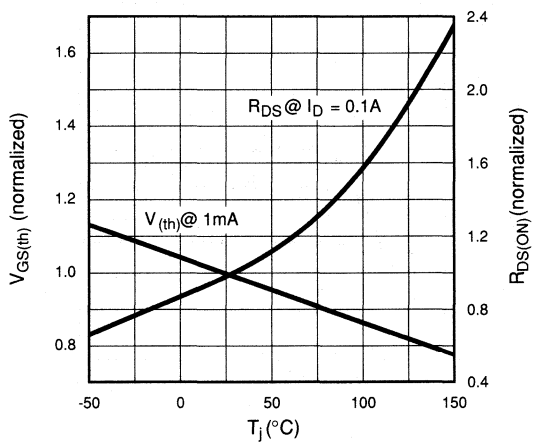
On-Resistance vs. Drain Current



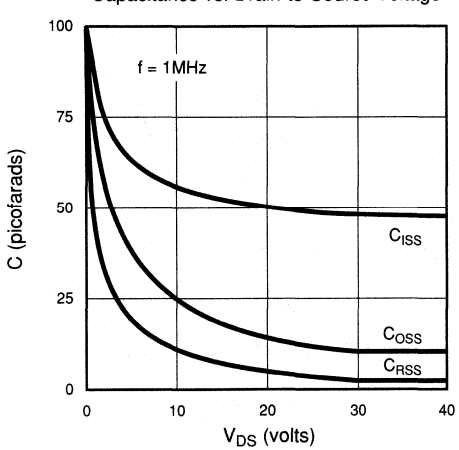
Transfer Characteristics



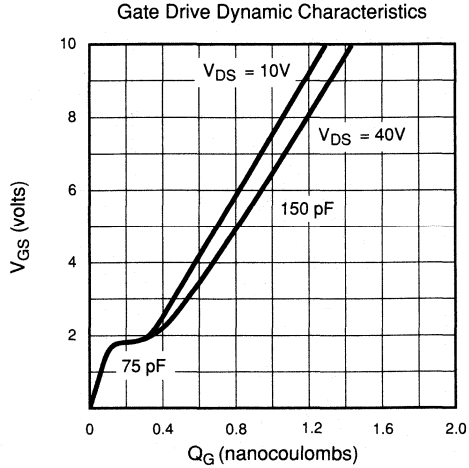
$V_{(th)}$ and R_{DS} Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package					
				TO-39	TO-92	TO-220	Quad P-DIP	Quad C-DIP*	DICE†
60V	1.5Ω	3.0A	1.6V	TN0606N2	TN0606N3	TN0606N5	TN0606N6	TN0606N7	TN0606ND
100V	1.5Ω	3.0A	1.6V	TN0610N2	TN0610N3	TN0610N5	—	—	TN0610ND

* 14 pin side brazed ceramic DIP
† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Low threshold — 1.6V max.
- ☐ High input impedance
- ☐ Low input capacitance — 100 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

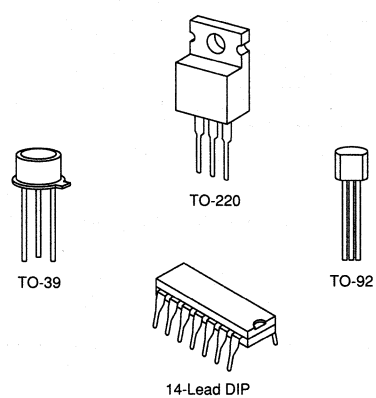
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Notes 1 and 2)



Note 1: See Package Outline section for discrete pinouts.
Note 2: See Array section for quad pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-92	0.8A	3.2A	1W	125	170	0.8A	3.2A
TO-39	1.5A	4A	6W	20	125	1.5A	4.0A
TO-220	3.0A	4.1A	45W	2.7	70	3.0A	4.1A
PLASTIC DIP	Refer to Arrays & Special Functions Section.						
CERAMIC DIP							

* I_D (continuous) is limited by max rated T_j.

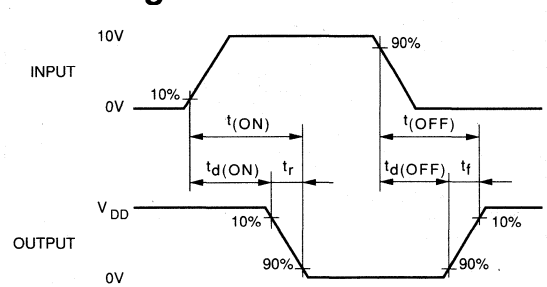
Electrical Characteristics (@ 25°C unless otherwise specified)

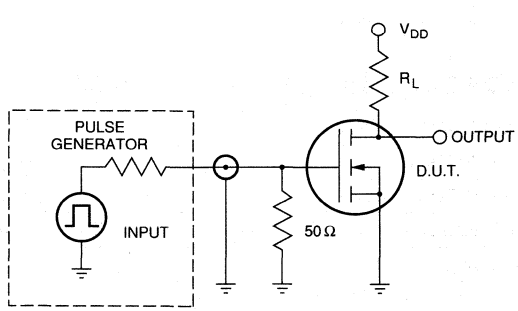
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TN0610	100			V	V_{GS} = 0, I_D = 1mA
		TN0606	60				
$V_{GS(th)}$	Gate Threshold Voltage		0.6		1.6	V	V_{GS} = V_{DS}, I_D = 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				-4.5	mV/°C	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C (note 2)
$I_{D(ON)}$	ON-State Drain Current		1.2	2.0		A	V_{GS} = 5V, V_{DS} = 25V
			3.0	6.7			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			1.5	2.0	Ω	V_{GS} = 5V, I_D = 0.75A
				1.0	1.5		V_{GS} = 10V, I_D = 0.75A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				0.75	%/°C	
G_{FS}	Forward Transconductance		0.4	0.5		℧	V_{DS} = 25V, I_D = 1.0A
C_{ISS}	Input Capacitance			100	150	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			50	85		
C_{RSS}	Reverse Transfer Capacitance			10	35	ns	V_{DD} = 25V I_D = 1.5A R_S = 50Ω
$t_{d(ON)}$	Turn-ON Delay Time				10		
t_r	Rise Time				10		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				10		
V_{SD}	Diode Forward Voltage Drop			0.8	1.8	V	V_{GS} = 0, I_{SD} = 1.5A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 1.5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

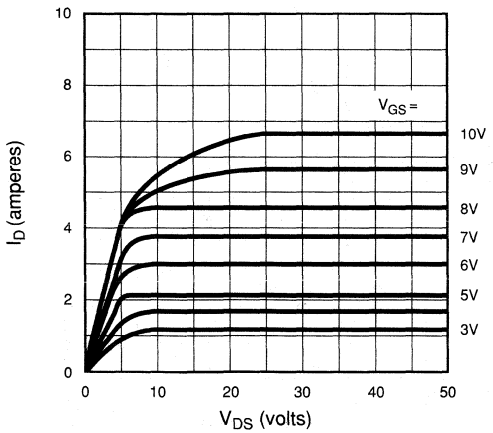
Switching Waveforms and Test Circuit



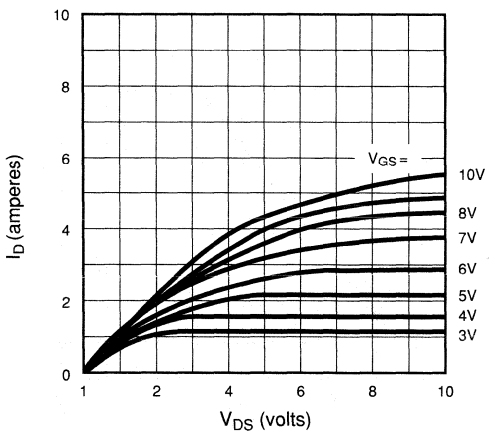


Typical Performance Curves

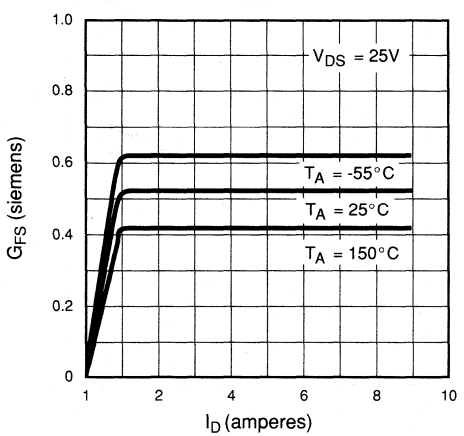
Output Characteristics



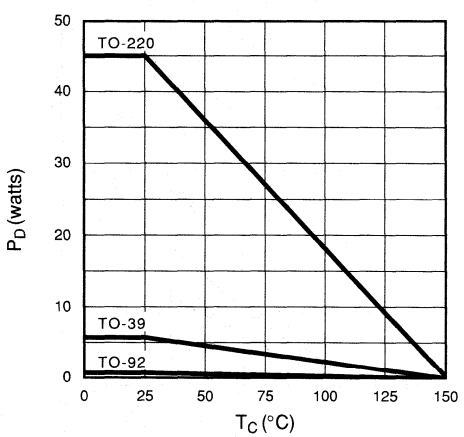
Saturation Characteristics



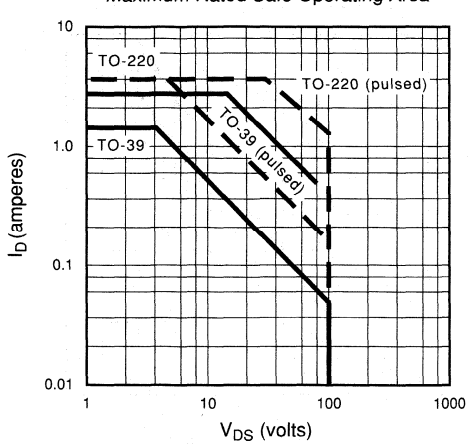
Transconductance vs. Drain Current



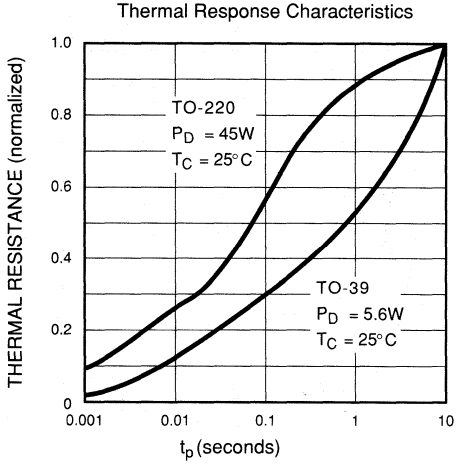
Power Dissipation vs. Case Temperature



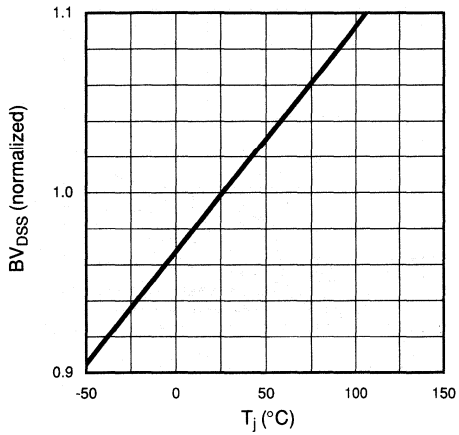
Maximum Rated Safe Operating Area



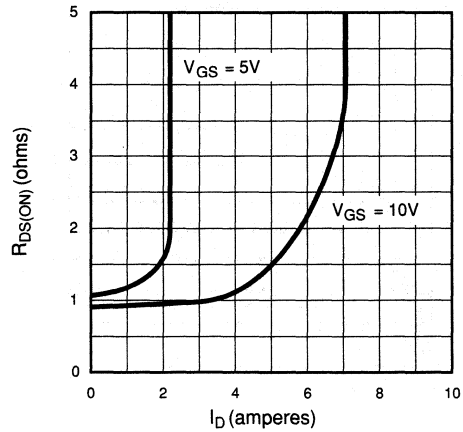
Thermal Response Characteristics



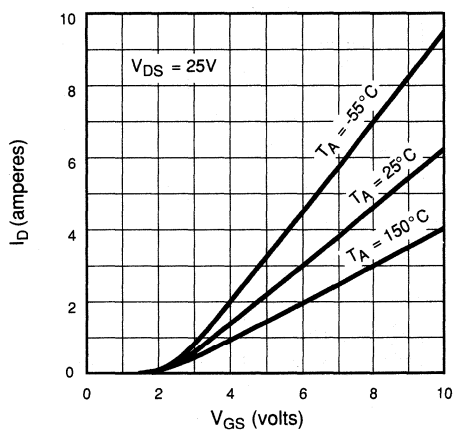
BV$_{DSS}$ Variation with Temperature



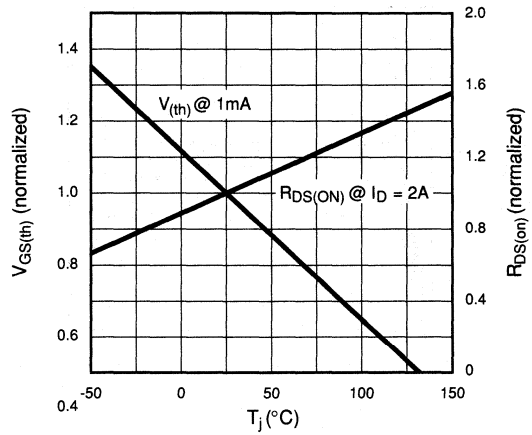
On-Resistance vs. Drain Current



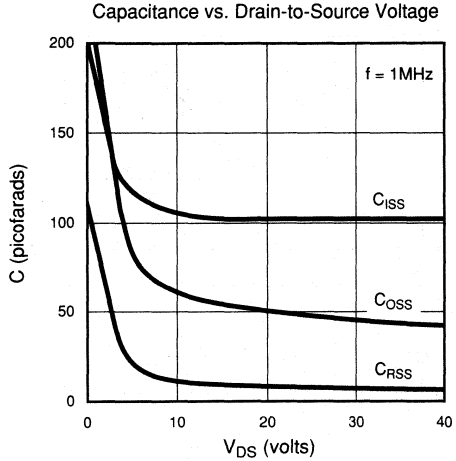
Transfer Characteristics



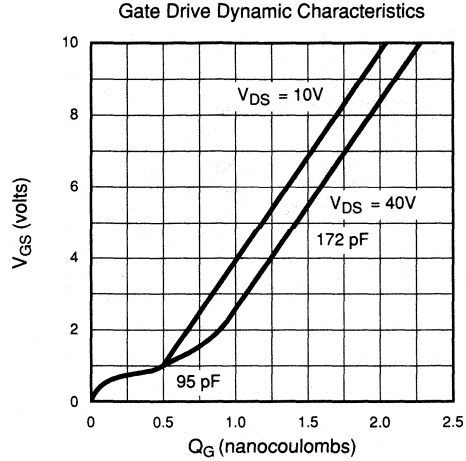
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package			
				TO-39	TO-92	TO-220	DICE†
200V	6Ω	1.0A	1.6V	TN0620N2	TN0620N3	TN0620N5	TN0620ND
240V	6Ω	1.0A	1.6V	TN0624N2	TN0624N3	TN0624N5	TN0624ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Low threshold — 1.6V max.
- ☐ High input impedance
- ☐ Low input capacitance — 110 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

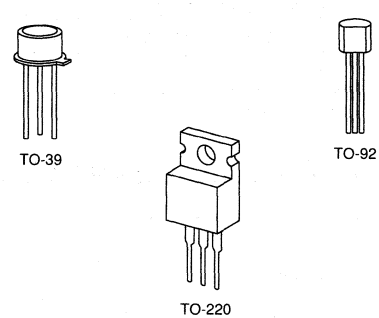
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-39	0.7A	2.5A	6W	20	125	0.7A	2.5A
TO-92	0.4A	2.0A	1W	125	170	0.4A	2.0A
TO-220	1.5A	2.5A	45W	2.7	70	1.5A	2.5A

* I_D (continuous) is limited by max rated T_j.

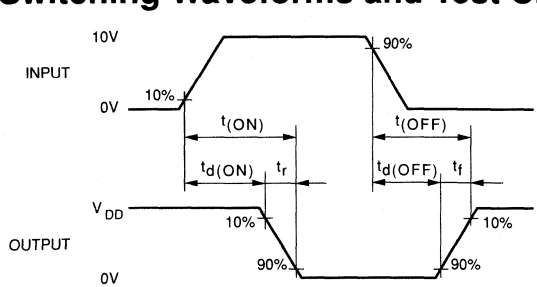
Electrical Characteristics (@ 25°C unless otherwise specified)

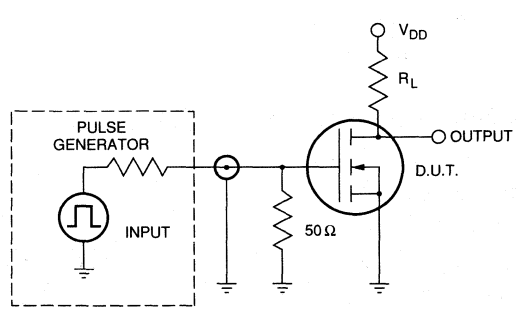
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TN0624	240			V	V_{GS} = 0, I_D = 2.0mA
		TN0620	200				
$V_{GS(th)}$	Gate Threshold Voltage		0.6		1.6	V	V_{GS} = V_{DS}, I_D = 1.0mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				-5.0	mV/°C	V_{GS} = V_{DS}, I_D = 1.0mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		0.5			A	V_{GS} = 5V, V_{DS} = 25V
			1.0				V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			6	8	Ω	V_{GS} = 5V, I_D = 0.25A
				4	6		V_{GS} = 10V, I_D = 0.5A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				1.4	%/°C	V_{GS} = 10V, I_D = 0.5A
G_{FS}	Forward Transconductance		300			m℧	V_{DS} = 25V, I_D = 0.5A
C_{ISS}	Input Capacitance			110	150	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			40	85		
C_{RSS}	Reverse Transfer Capacitance			10	35		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = 25V I_D = 1.0A R_S = 50Ω
t_r	Rise Time				6		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				20		
V_{SD}	Diode Forward Voltage Drop				1.8	V	V_{GS} = 0, I_{SD} = 1.0A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 1.0A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

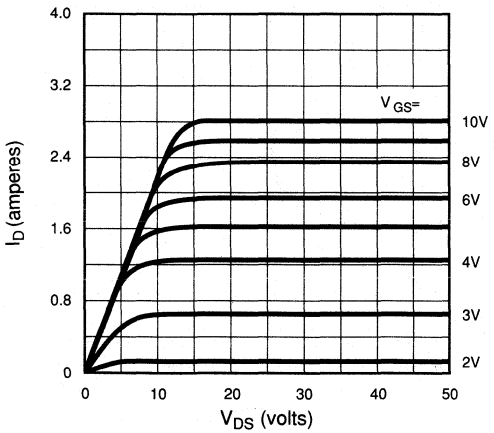
Switching Waveforms and Test Circuit



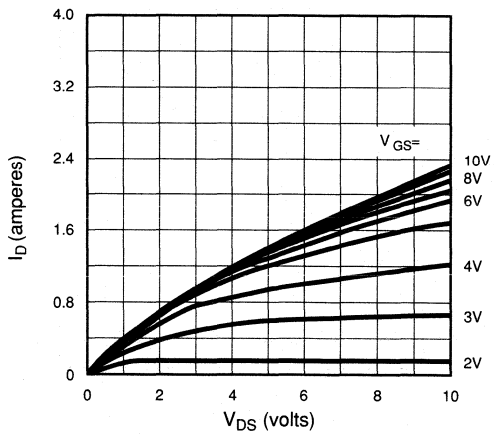


Typical Performance Curves

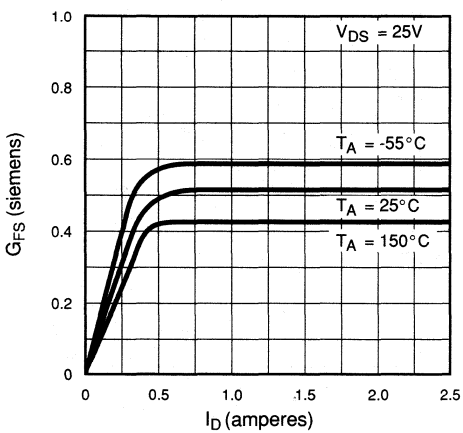
Output Characteristics



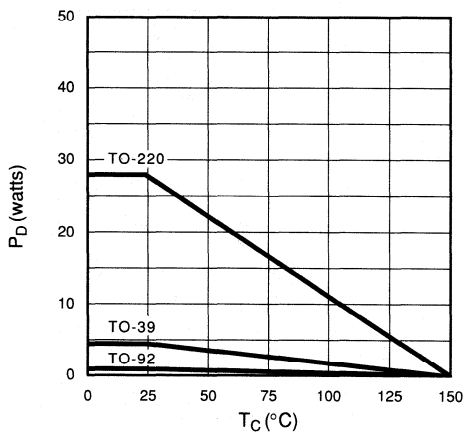
Saturation Characteristics



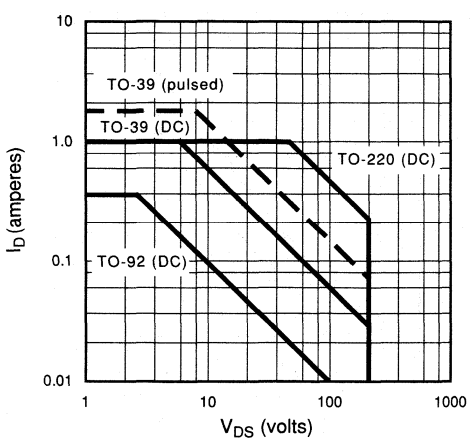
Transconductance vs. Drain Current



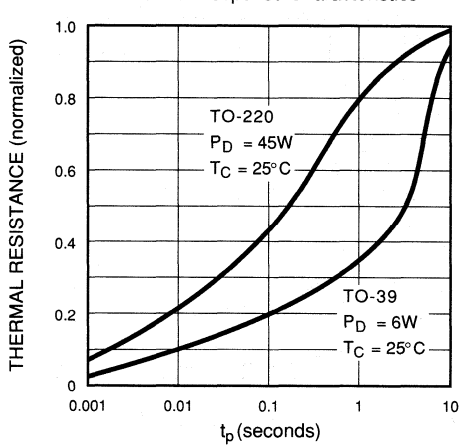
Power Dissipation vs. Case Temperature



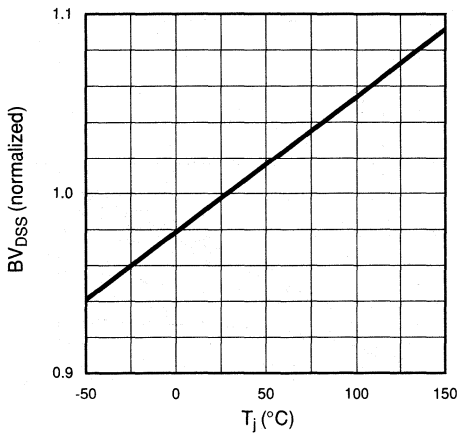
Maximum Rated Safe Operating Area



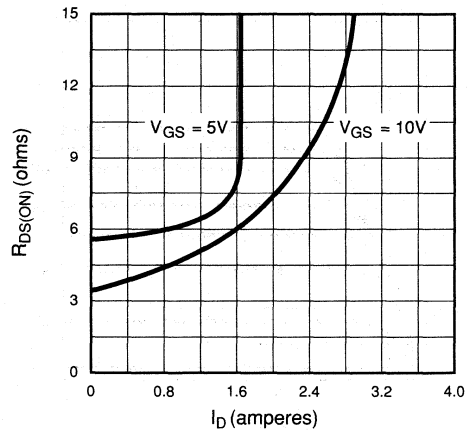
Thermal Response Characteristics



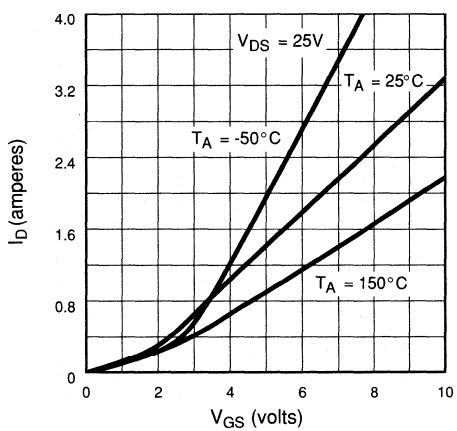
BV$_{DSS}$ Variation with Temperature



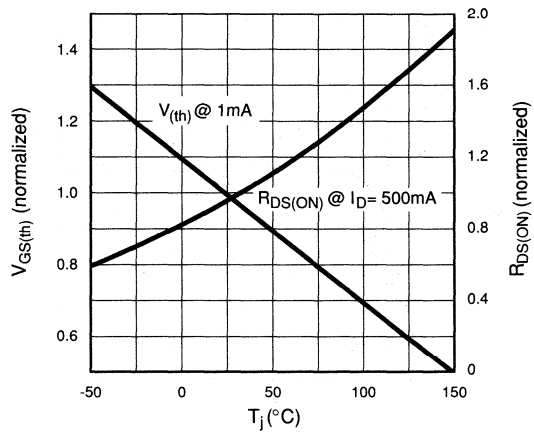
On-Resistance vs. Drain Current



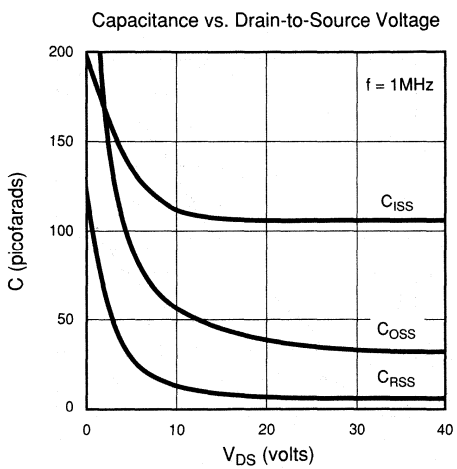
Transfer Characteristics



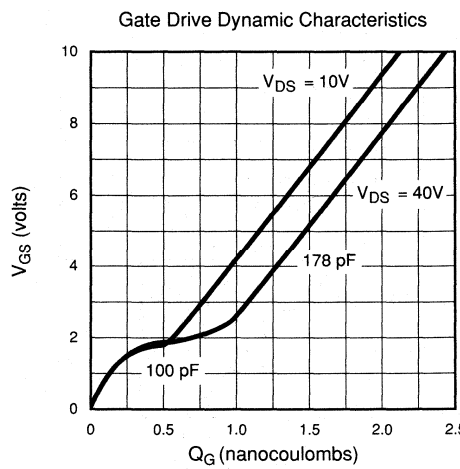
$V_{(th)}$ and R_{DS} Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package	
				TO-92	DICE†
350V	10Ω	1.0A	1.8V	TN0635N3	TN0635ND
400V	10Ω	1.0A	1.8V	TN0640N3	TN0640ND

† MIL visual screening available

Features

- ☐ Low threshold —1.8V max.
- ☐ High input impedance
- ☐ Low input capacitance — 85 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

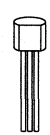
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-92	200mA	1.5A	1.0W	170	125	200mA	1.5A

* I_D (continuous) is limited by max rated T_j.

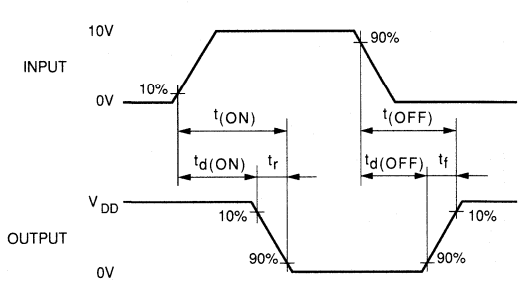
Electrical Characteristics (@ 25°C unless otherwise specified)

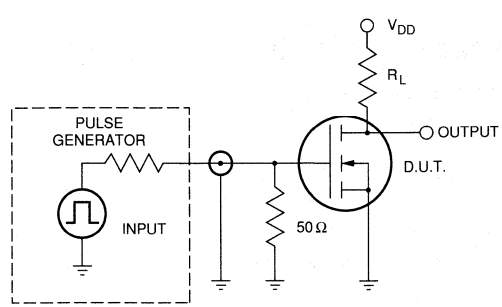
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TN0640	400			V	V_{GS} = 0, I_D = 100µA
		TN0635	350				
$V_{GS(th)}$	Gate Threshold Voltage		0.6		1.8	V	V_{GS} = V_{DS}, I_D= 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-2.5	-4.0	mV/°C	V_{GS} = V_{DS}, I_D= 1mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10		V_{GS} = 0, V_{DS} = Max Rating
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		0.3	1.5		mA	V_{GS} = 5V, V_{DS} = 25V
			1.0	1.8			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			8	10	Ω	V_{GS} = 4.5V, I_D = 150mA
				8	10		V_{GS} = 10V, I_D = 0.5A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				0.75	%/°C	V_{GS} = 10V, I_D = 500mA
G_{FS}	Forward Transconductance		125			m ℧	V_{DS} = 25V, I_D = 100mA
C_{ISS}	Input Capacitance			85	130	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			25	75		
C_{RSS}	Reverse Transfer Capacitance			10	20		
$t_{d(ON)}$	Turn-ON Delay Time				20	ns	V_{DD} = 25V, I_D =0.5A, R_S = 50Ω
t_r	Rise Time				15		
$t_{d(OFF)}$	Turn-OFF Delay Time				25		
t_f	Fall Time				20		
V_{SD}	Diode Forward Voltage Drop				1.8	V	V_{GS} = 0, I_{SD} = 200mA
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 1.0A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

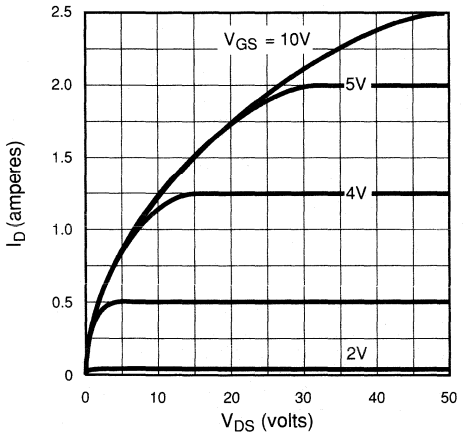
Switching Waveforms and Test Circuit



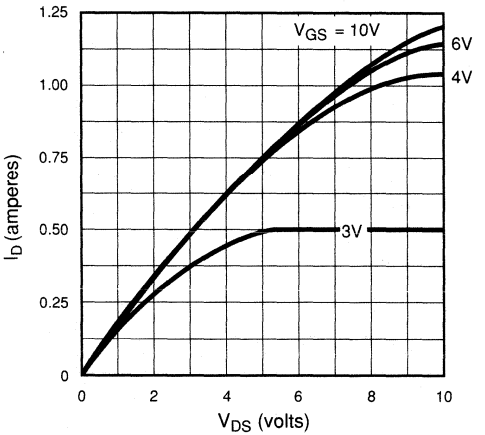


Typical Performance Curves

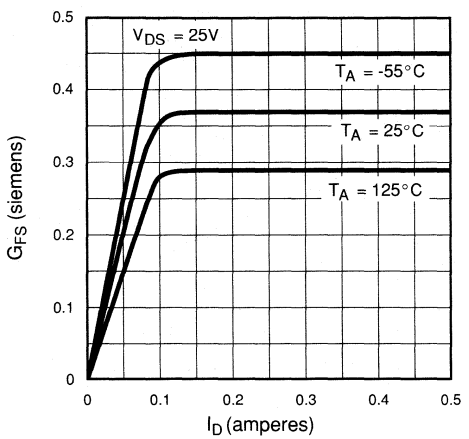
Output Characteristics



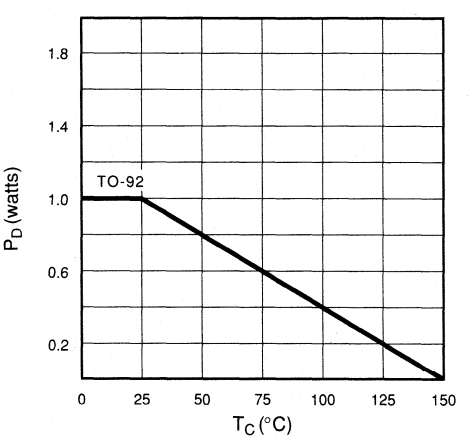
Saturation Characteristics



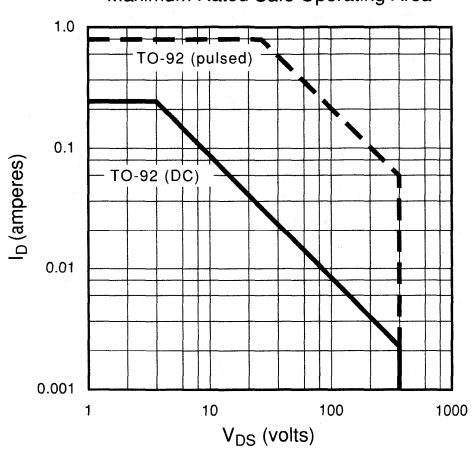
Transconductance vs. Drain Current



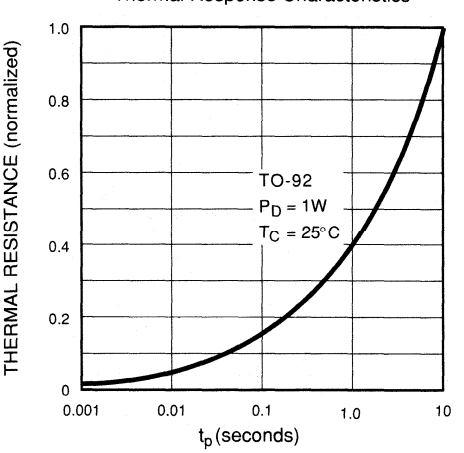
Power Dissipation vs. Case Temperature



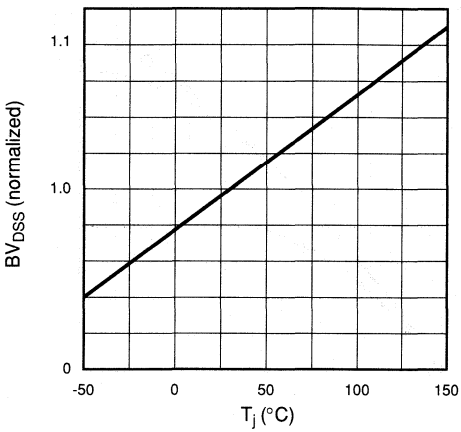
Maximum Rated Safe Operating Area



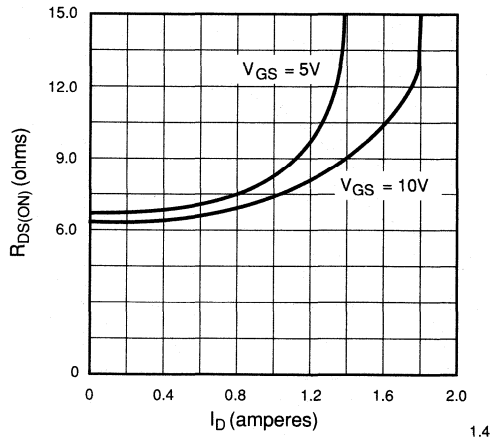
Thermal Response Characteristics



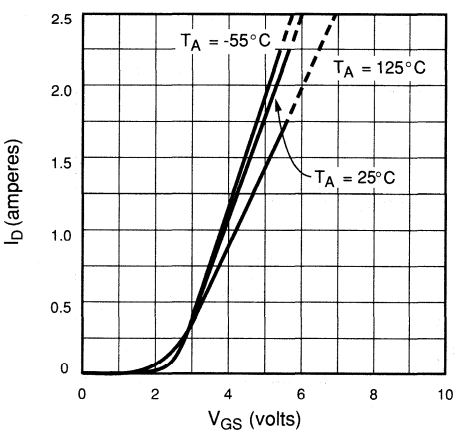
BV$_{DSS}$ Variation with Temperature



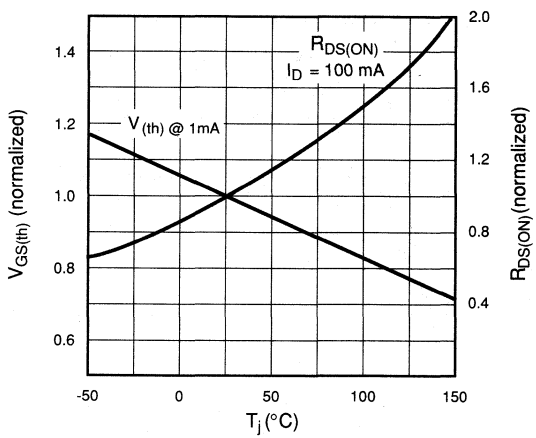
On-Resistance vs. I $_D$



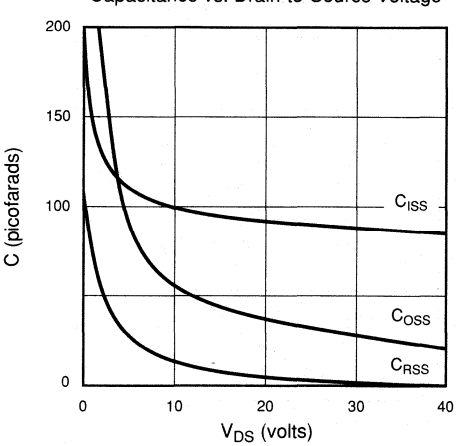
Transfer Characteristics



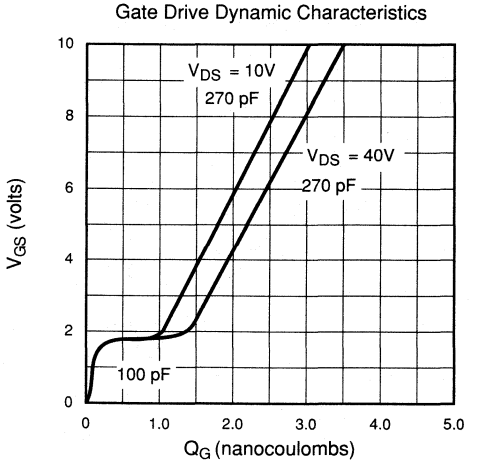
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package			
				TO-39	TO-92	SOW-20*	DICE†
20V	0.75Ω	4.0A	1.6V	—	TN0602N3	—	TN0602ND
20V	0.85Ω	4.0A	1.6V	TN0602N2	—	—	—
40V	0.75Ω	4.0A	1.6V	—	TN0604N3	—	TN0604ND
40V	0.85Ω	4.0A	1.6V	TN0604N2	—	—	—
40V	1.0 Ω	4.0A	1.6V	—	—	TN0604WG	—

* Same as SO-20 with 300 mil wide body.
† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Low threshold — 1.6V max.
- ☐ High input impedance
- ☐ Low input capacitance — 85 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

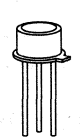
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

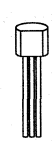
These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

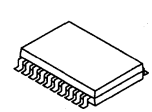
Package Options (Notes 1 and 2)



TO-39



TO-92



SOW-20

Note 1: See Package Outline section for discrete pinouts.
Note 2: See Array section for quad pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-39	2.5A	4.6A	6W	20	125	2.5A	4.6A
TO-92	1.0A	4.6A	1W	125	170	1.0A	4.6A
SOW-20	Refer to Arrays & Special Functions Section.						

* I_D (continuous) is limited by max rated T_j.

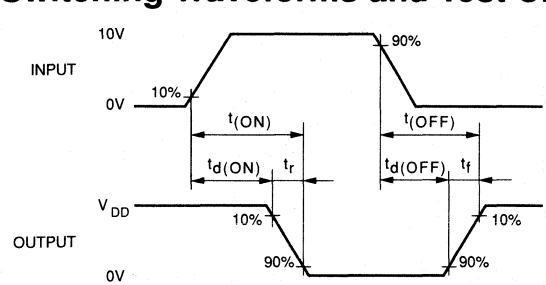
Electrical Characteristics (@ 25°C unless otherwise specified)

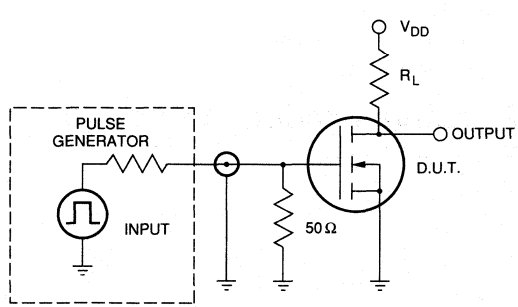
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TN0604	40			V	V_{GS}= 0, I_D = 2.0mA
		TN0602	20				
$V_{GS(th)}$	Gate Threshold Voltage		0.6		1.6	V	V_{GS} = V_{DS}, I_D = 1.0mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.8	-4.5	mV/°C	V_{GS} = V_{DS}, I_D = 2.5mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		1.5	2.1		A	V_{GS} = 5V, V_{DS} = 25V
			4.0	7.0			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	All Packages		0.8	1.5	Ω	V_{GS} = 5V, I_D = 1.0A
		TO-92		0.60	0.75		V_{GS} = 10V, I_D = 2.0A
		TO-39			0.85		
		SOW - 20			1.0		
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.5	0.75	%/°C	V_{GS} = 10V, I_D = 2.0A
G_{FS}	Forward Transconductance		0.5			℧	V_{DS} = 25V, I_D = 2.0A
C_{ISS}	Input Capacitance			140	190	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			75	110		
C_{RSS}	Reverse Transfer Capacitance			25	50	ns	V_{DD} = 25V I_D = 0.5A R_S = 50Ω
$t_{d(ON)}$	Turn-ON Delay Time				10		
t_r	Rise Time				6		
$t_{d(OFF)}$	Turn-OFF Delay Time				25		
t_f	Fall Time				13		
V_{SD}	Diode Forward Voltage Drop			1.2	1.8	V	V_{GS} = 0, I_{SD} = 1.5A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 1A

Notes:
1: All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2: All A.C. parameters sample tested.

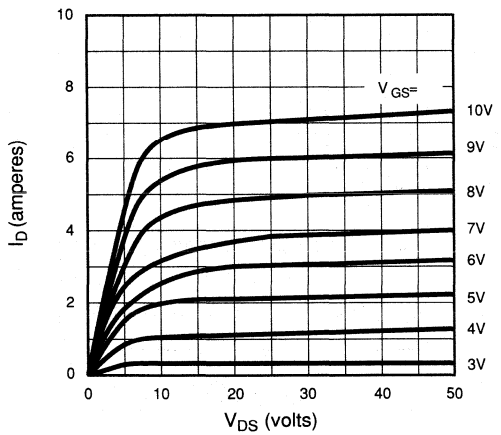
Switching Waveforms and Test Circuit



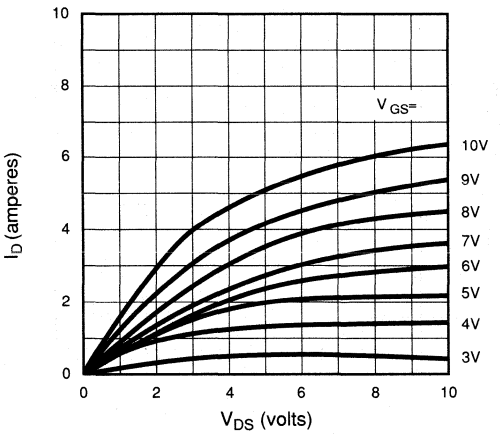


Typical Performance Curves

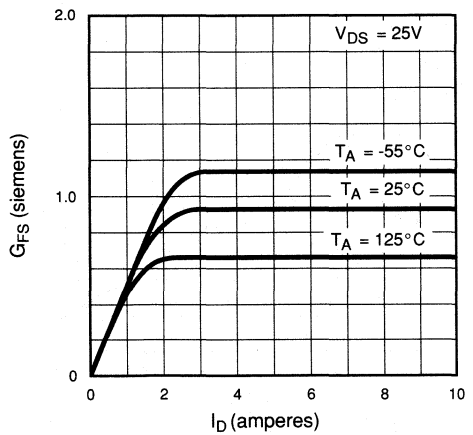
Output Characteristics



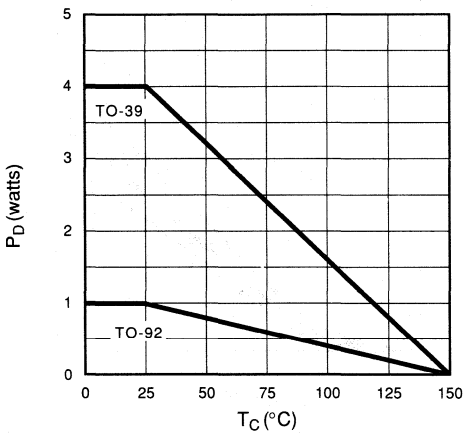
Saturation Characteristics



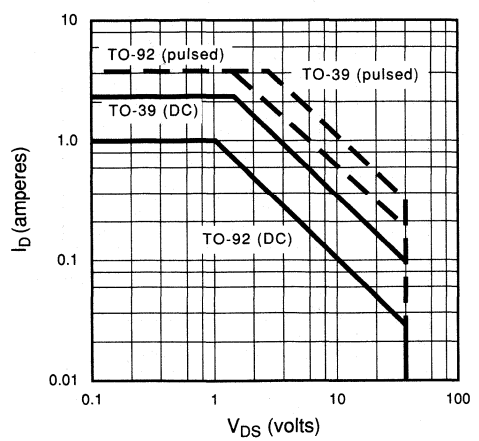
Transconductance vs. Drain Current



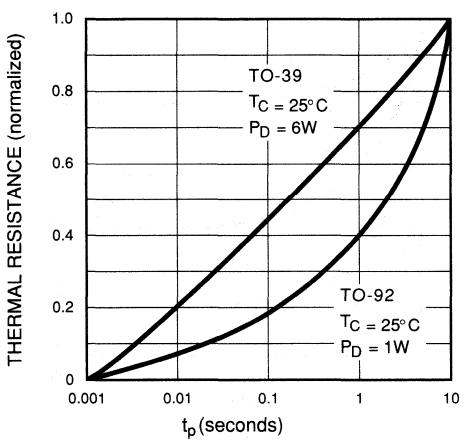
Power Dissipation vs. Case Temperature



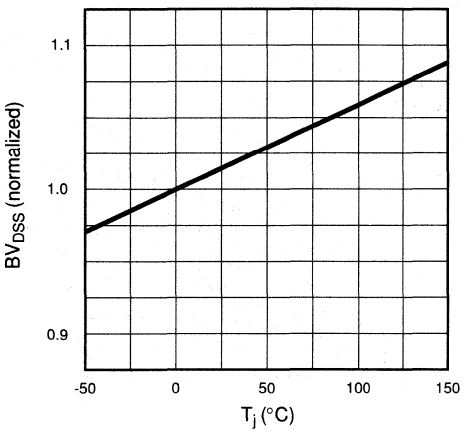
Maximum Rated Safe Operating Area



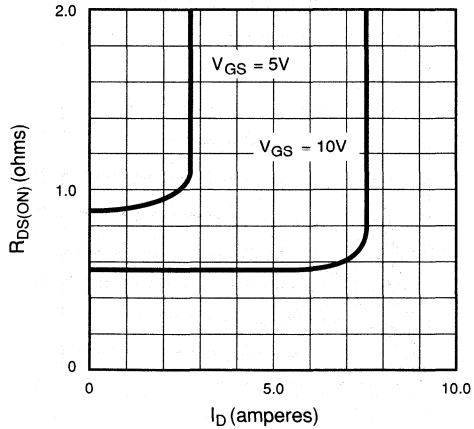
Thermal Response Characteristics



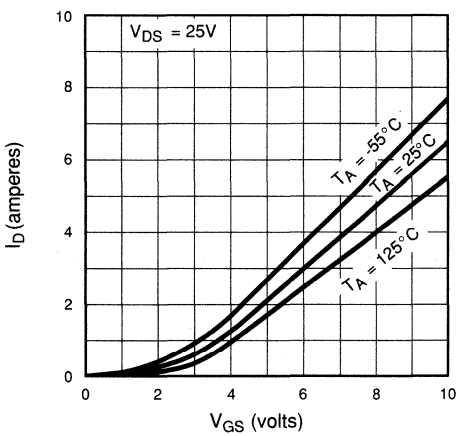
BV$_{DSS}$ Variation with Temperature



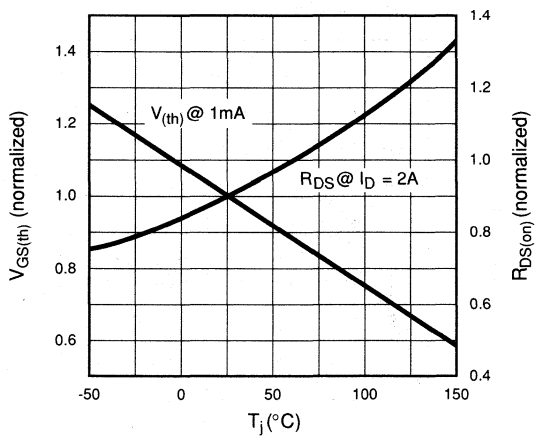
On-Resistance vs. Drain Current



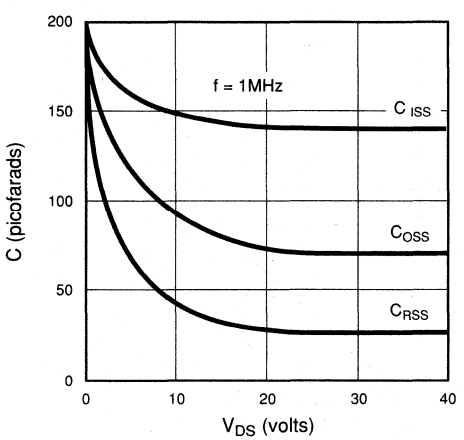
Transfer Characteristics



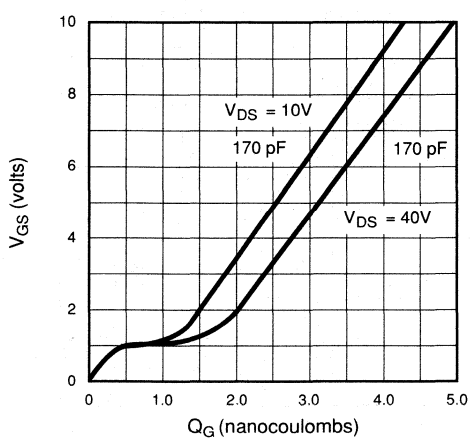
$V_{(th)}$ and R_{DS} Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package	
				TO-92	DICE†
20V	1.3Ω	0.5A	1.0V	TN0702N3	TN0702ND

† MIL visual screening available

Features

- ☐ Low threshold — 1.0 max
- ☐ On resistance guaranteed at V_{GS} = 2, 3, and 5 volts
- ☐ High input impedance
- ☐ Low input capacitance —130 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage

Applications

- ☐ Logic level interface
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

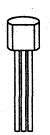
*Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-92	0.6A	0.75A	1W	125	170	0.6A	0.75A

* I_D (continuous) is limited by max rated T_j.

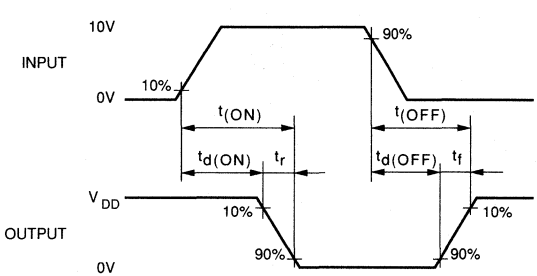
Electrical Characteristics (@ 25°C unless otherwise specified)

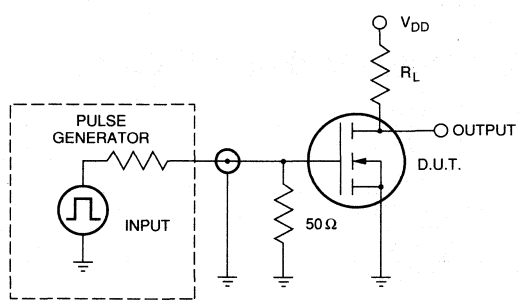
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	20			V	V_{GS} = 0, I_D = 1mA
$V_{GS(th)}$	Gate Threshold Voltage	0.5	0.8	1.0	V	V_{GS} = V_{DS}, I_D = 1.0mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-4.0	mV/°C	V_{GS} = V_{DS}, I_D = 1.0mA
I_{GSS}	Gate Body Leakage			100	nA	V_{GS} = ±20V, V_{DS} = 0V
I_{DSS}	Zero Gate Voltage Drain Current			100	nA	V_{DS} = 20V, V_{GS} = 0V
				100	µA	V_{DS} = 0.8 Max Rating, V_{GS} = 0V, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	0.5	1.0		A	V_{GS} = V_{DS} = 5V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance		4.0	5.0	Ω	V_{GS} = 2V, I_D = 50mA
			1.9	2.5		V_{GS} = 3V, I_D = 200mA
			1.0	1.3		V_{GS} = 5V, I_D =500mA
G_{FS}	Forward Transconductance	100			m℧	V_{DS} = 5V, I_D = 500mA
C_{ISS}	Input Capacitance		130	200	pF	V_{GS} = 0V, V_{DS} = 20V, f =1MHz
C_{OSS}	Common Source Output Capacitance		70	125		
C_{RSS}	Reverse Transfer Capacitance		30	60		
$t_{d(ON)}$	Turn-ON Delay Time			20	ns	V_{DD} = 20V, I_D = 0.5A, R_S = 50Ω
t_r	Rise Time			20		
$t_{d(OFF)}$	Turn-OFF Delay Time			30		
t_f	Fall Time			20		
V_{SD}	Diode Forward Voltage Drop			1.0	V	V_{GS} = 0V, I_{SD} = 0.5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwide stated. (Pulse test: 300 µs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





Preliminary

N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$V_{GS(th)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
				TO-243AA*	DICE†
60V	1.5Ω	1.6V	3.0A	—	TN2506ND
100V	1.5Ω	1.6V	3.0A	TN2510N8	TN2510ND

* Same as SOT-89.
† MIL visual screening available.

Features

- ☐ Low threshold —1.6V max.
- ☐ High input impedance
- ☐ Low input capacitance — 125 pF max.
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

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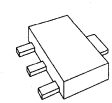
Package Options (Note 1)



TO-243AA
(SOT-89)

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-243AA	0.42A	3.0A	0.55W†	227†	—	0.42A	3.0A

* I_D (continuous) is limited by max rated T_j.
† Mounted on FR5 board, 25mm x 19mm x 1.57mm. Significant P_D increase possible on ceramic substrate.

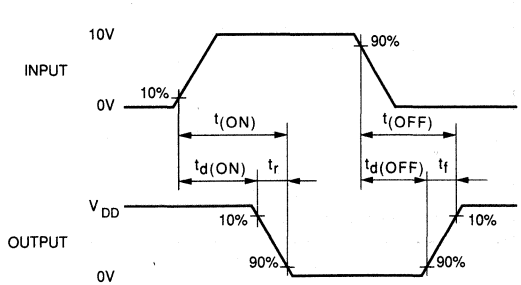
Electrical Characteristics (@ 25°C unless otherwise specified)

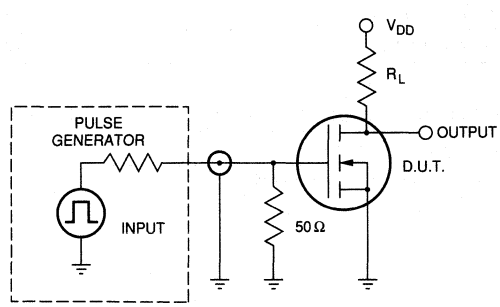
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TN2510	100			V	V_{GS} = 0, I_D = 2mA
		TN2506	60				
$V_{GS(th)}$	Gate Threshold Voltage		0.6		1.6	V	V_{GS} = V_{DS}, I_D= 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				-4.5	mV/°C	V_{GS} = V_{DS}, I_D= 1.0mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		1.2	2.0		A	V_{GS} = 5V, V_{DS} = 25V
			3.0	6.0			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			1.5	2.0	Ω	V_{GS} = 5V, I_D = 750mA
				1.0	1.5		V_{GS} = 10V, I_D = 750mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				0.75	%/°C	V_{GS} = 10V, I_D = 0.5A
G_{FS}	Forward Transconductance		0.4	0.6		℧	V_{DS} = 25V, I_D = 1.0A
C_{ISS}	Input Capacitance				125	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance				70		
C_{RSS}	Reverse Transfer Capacitance				25		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = 25V, I_D = 1.5A, R_S = 50Ω
t_r	Rise Time				10		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				10		
V_{SD}	Diode Forward Voltage Drop				1.8	V	V_{GS} = 0, I_{SD} = 1.5A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 1.5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$V_{GS(th)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
				TO-243AA*	DICE
200V	6Ω	2.0V	1.0A	—	TN2520ND
240V	6Ω	2.0V	1.0A	TN2524N8	TN2524ND

* Same as SOT-89.

Features

- ☐ Low threshold — 2.0V max.
- ☐ High input impedance
- ☐ Low input capacitance — 125 pF max.
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

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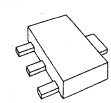
Package Options (Note 1)



TO-243AA
(SOT-89)

Note 1: See package outline section for decrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-243AA	0.2A	1.8A	0.55W†	227†	—	0.2A	1.8A

* I_D (continuous) is limited by max rated T_j.
† Mounted on FR5 board, 25mm x 19mm x 1.57mm. Significant P_D increase possible on ceramic substrate.

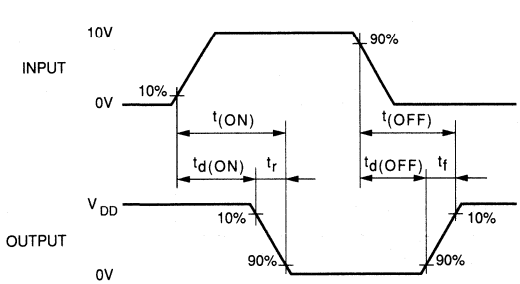
Electrical Characteristics (@ 25°C unless otherwise specified)

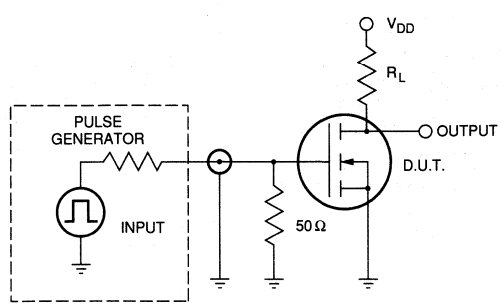
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TN2524	240			V	V_{GS} = 0, I_D = 2mA
		TN2520	200				
$V_{GS(th)}$	Gate Threshold Voltage		0.6		2.0	V	V_{GS} = V_{DS}, I_D= 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				-5.0	mV/°C	V_{GS} = V_{DS}, I_D= 1mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		0.5			A	V_{GS} = 4.5V, V_{DS} = 25V
			1.0				V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			4	6	Ω	V_{GS} = 4.5V, I_D = 250mA
				4	6		V_{GS} = 10V, I_D = 0.5A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				1.4	%/°C	V_{GS} = 10V, I_D = 0.5A
G_{FS}	Forward Transconductance		300			m℧	V_{DS} = 25V, I_D = 0.5A
C_{ISS}	Input Capacitance				125	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance				70		
C_{RSS}	Reverse Transfer Capacitance				25		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = 25V, I_D = 1.0A, R_S = 50Ω
t_r	Rise Time				10		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				20		
V_{SD}	Diode Forward Voltage Drop				1.8	V	V_{GS} = 0, I_{SD} = 1.0A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 1.0A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$V_{GS(th)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
				TO-243AA*	DICE†
350V	12Ω	1.8V	1.0A	—	TN2535ND
400V	12Ω	1.8V	1.0A	TN2540N8	TN2540ND

* Same as SOT-89.
† MIL visual screening available.

Features

- ☐ Low threshold — 1.8V max.
- ☐ High input impedance
- ☐ Low input capacitance — 125 pF max.
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

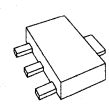
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-243AA
(SOT-89)

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-243AA	165mA	1.0A	0.55W†	227†	—	165mA	1.0A

* I_D (continuous) is limited by max rated T_j.
† Mounted on FR5 board, 25mm x 19mm x 1.57mm. Significant P_D increase possible on ceramic substrate.

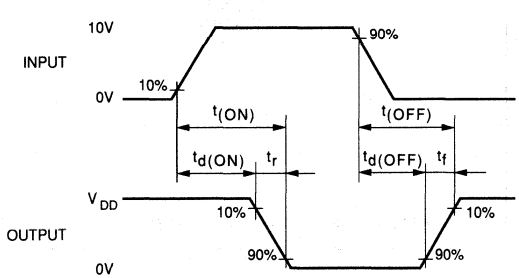
Electrical Characteristics (@ 25°C unless otherwise specified)

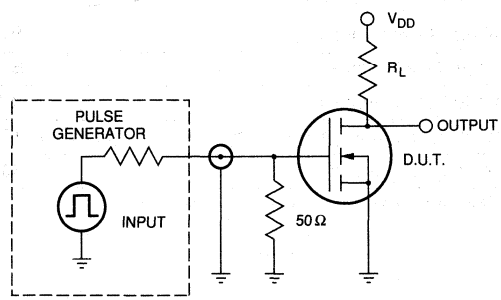
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TN2540	400			V	V_{GS} = 0, I_D = 100µA
		TN2535	350				
$V_{GS(th)}$	Gate Threshold Voltage		0.6		1.8	V	V_{GS} = V_{DS}, I_D= 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-2.5	-4.0	mV/°C	V_{GS} = V_{DS}, I_D= 1mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		0.3	1.5		A	V_{GS} = 4.5V, V_{DS} = 25V
			1.0	1.8			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			8	12	Ω	V_{GS} = 4.5V, I_D = 150mA
				8	12		V_{GS} = 10V, I_D = 0.5A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				0.75	%/°C	V_{GS} = 10V, I_D = 500mA
G_{FS}	Forward Transconductance		125			m℧	V_{DS} = 25V, I_D = 100mA
C_{ISS}	Input Capacitance				125	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance				70		
C_{RSS}	Reverse Transfer Capacitance				25		
$t_{d(ON)}$	Turn-ON Delay Time				20	ns	V_{DD} = 25V, I_D = 500mA, R_S = 50Ω
t_r	Rise Time				15		
$t_{d(OFF)}$	Turn-OFF Delay Time				25		
t_f	Fall Time				20		
V_{SD}	Diode Forward Voltage Drop				1.8	V	V_{GS} = 0, I_{SD} = 200mA
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

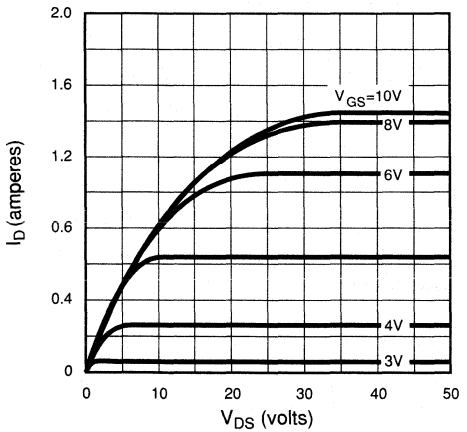
Switching Waveforms and Test Circuit



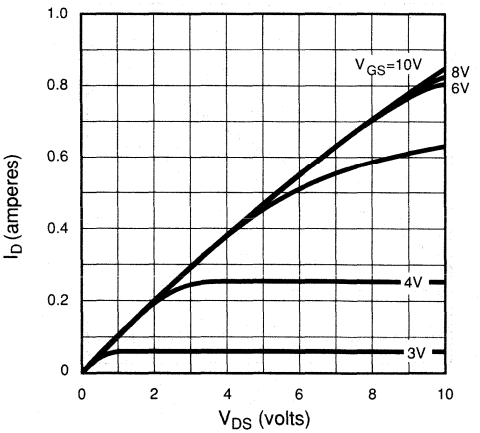


Typical Performance Curves

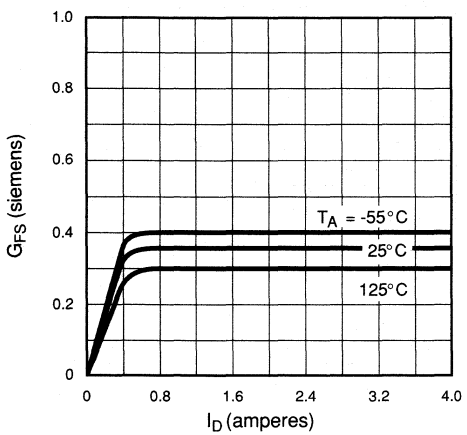
Output Characteristics



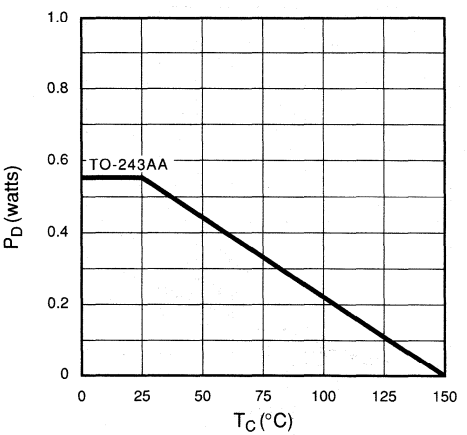
Saturation Characteristics



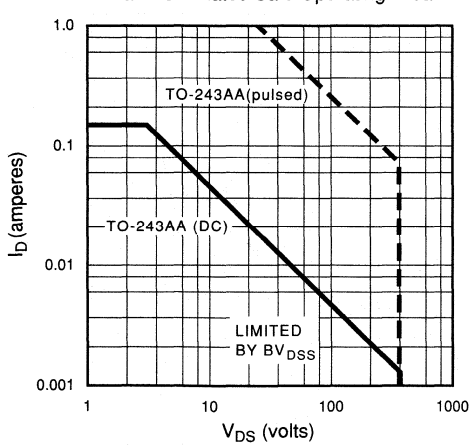
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

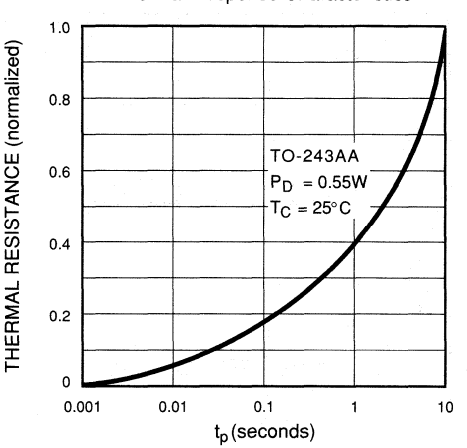


Maximum Rated Safe Operating Area

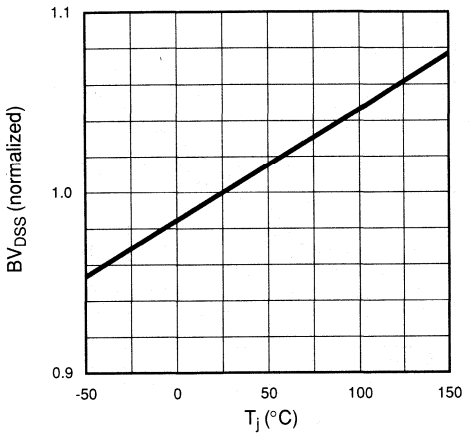


Pulsed Condition: 300 µs; 20% Duty Cycle

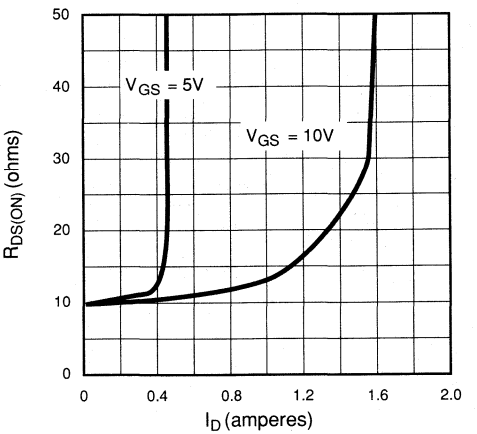
Thermal Response Characteristics



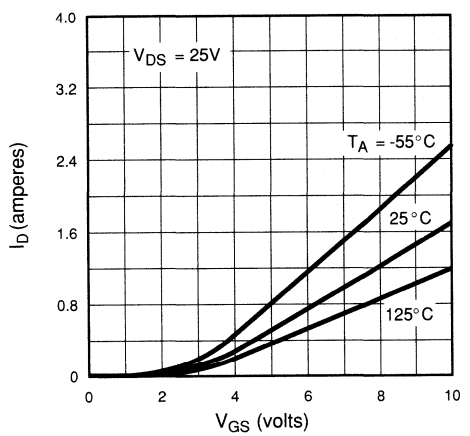
BV_{DSS} Variation with Temperature



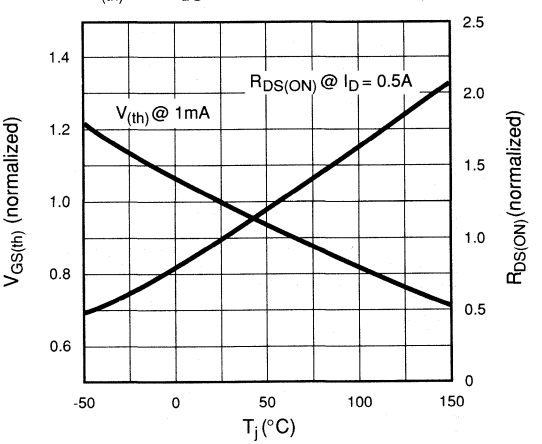
On-Resistance vs. Drain Current



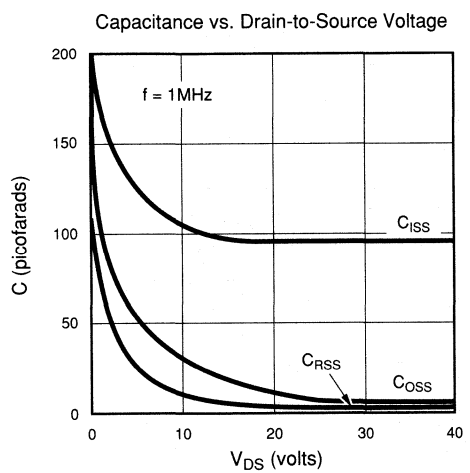
Transfer Characteristics



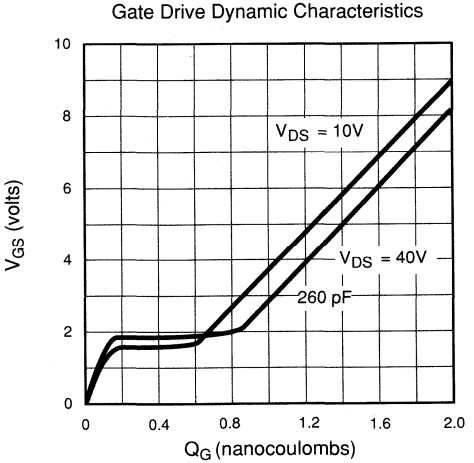
$V_{(th)}$ and R_{DS} Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$V_{GS(th)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
				TO-243AA*	DICE†
20V	1.0Ω	1.6V	4.0A	—	TN2502ND
40V	1.0Ω	1.6V	4.0A	TN2504N8	TN2504ND

* Same as SOT-89.
† MIL visual screening available.

Features

- ☐ Low threshold — 1.6V max.
- ☐ High input impedance
- ☐ Low input capacitance — 125 pF max.
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

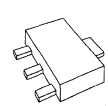
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-243AA
(SOT-89)

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-243AA	0.6A	4.0A	0.55W†	227†	—	0.6A	4.0A

* I_D (continuous) is limited by max rated T_j.
† Mounted on FR5 board, 25mm x 19mm x 1.57mm. Significant P_D increase possible on ceramic substrate.

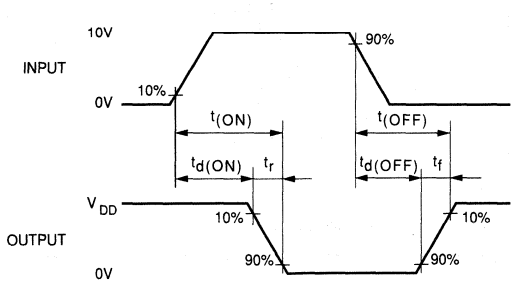
Electrical Characteristics (@ 25°C unless otherwise specified)

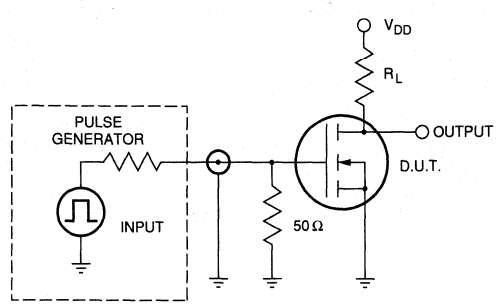
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TN2504	40			V	V_{GS} = 0, I_D = 2mA
		TN2502	20				
$V_{GS(th)}$	Gate Threshold Voltage		0.6		1.6	V	V_{GS} = V_{DS}, I_D= 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.8	-4.5	mV/°C	V_{GS} = V_{DS}, I_D= 2.5mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		1.0	2.1		A	V_{GS} = 5V, V_{DS} = 15V
			4.0	7.0			V_{GS} = 10V, V_{DS} = 15V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			0.8	1.5	Ω	V_{GS} = 5V, I_D = 750mA
				0.7	1.0		V_{GS} = 10V, I_D = 1.5A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				0.75	%/°C	V_{GS} = 10V, I_D = 2.0A
G_{FS}	Forward Transconductance		0.5	1.0		℧	V_{DS} = 15V, I_D = 2.0A
C_{ISS}	Input Capacitance				125	pF	V_{GS} = 0, V_{DS} = 15V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance				70		
C_{RSS}	Reverse Transfer Capacitance				25		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = 15V, I_D = 500mA, R_S = 50Ω
t_r	Rise Time				10		
$t_{d(OFF)}$	Turn-OFF Delay Time				25		
t_f	Fall Time				13		
V_{SD}	Diode Forward Voltage Drop			1.2	1.8	V	V_{GS} = 0, I_{SD} = 1.5A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$V_{GS(th)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package			
				TO-39	TO-92	TO-243AA*	DICE†
-20V	4.0Ω	-2.4V	-0.85A	TP0102N2	TP0102N3	—	TP0102ND
-40V	4.0Ω	-2.4V	-0.85A	TP0104N2	TP0104N3	TP0104N8	TP0104ND

* Same as SOT-89.
† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Low threshold — 2.4V max.
- ☐ High input impedance
- ☐ Low input capacitance — 52 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

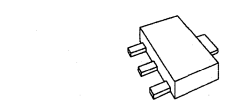
* For TO-39 and TO-92, distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

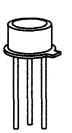
These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

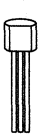
Package Options (Note 1)



TO-243AA
(SOT-89)



TO-39



TO-92

Note 1: See package outline section for decrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-39	-0.90A	-2.6A	3.50W	35	125	-0.90A	-2.6A
TO-92	-0.50A	-2.4A	1.00W	125	170	-0.50A	-2.4A
TO-243AA	-0.26A	-2.0A	0.55W†	—	—	-0.26A	-2.0A

* I_D (continuous) is limited by max rated T_j.
† Mounted on FR5 board, 25mm x 19mm x 1.57mm. Significant P_D increase possible on ceramic substrate.

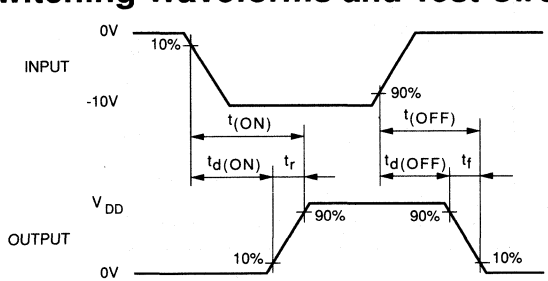
Electrical Characteristics (@ 25°C unless otherwise specified)

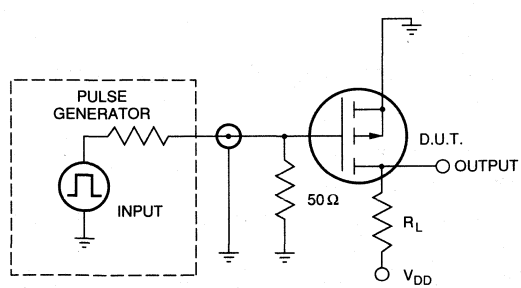
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TP0104	-40			V	V_{GS} = 0, I_D = -1.0mA
		TP0102	-20				
$V_{GS(th)}$	Gate Threshold Voltage		-1.0		-2.4	V	V_{GS} = V_{DS}, I_D = -1.0mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-5.8	-6.5	mV/°C	V_{GS} = V_{DS}, I_D = -1.0mA
I_{GSS}	Gate Body Leakage			-1.0	-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	µA	V_{GS} = 0, V_{DS} = Max Rating
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			-0.08		A	V_{GS} = -3V, V_{DS} = -25V
			-0.25	-0.50			V_{GS} = -5V, V_{DS} = -25V
			-0.85	-1.70			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			15		Ω	V_{GS} = -3V, I_D = -25mA
				5.5	7.5		V_{GS} = -5V, I_D = -0.1A
				2.5	4.0		V_{GS} = -10V, I_D = -0.5A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.55	1.0	%/°C	I_D = -0.5A, V_{GS} = -10V
G_{FS}	Forward Transconductance		225	250		m℧	V_{DS} = -25V, I_D = -0.5A
C_{ISS}	Input Capacitance			52	60	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			22	30		
C_{RSS}	Reverse Transfer Capacitance			3	8		
$t_{d(ON)}$	Turn-ON Delay Time			4	6	ns	V_{DD} = -25V, I_D = -1A, R_S = 50Ω
t_r	Rise Time			7	10		
$t_{d(OFF)}$	Turn-OFF Delay Time			3	5		
t_f	Fall Time			4	6		
V_{SD}	Diode Forward Voltage Drop			-1.2	-2.0	V	I_{SD} = -0.25A, V_{GS} = 0
t_{rr}	Reverse Recovery Time			300		ns	I_{SD} = -1.0A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

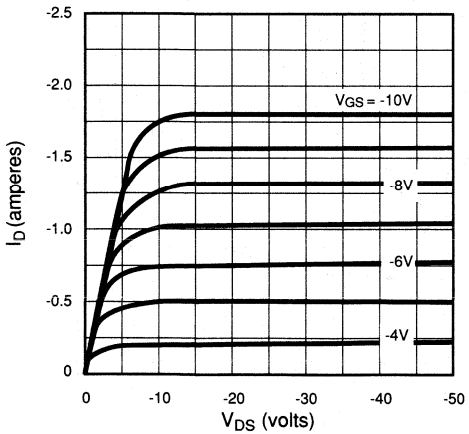
Switching Waveforms and Test Circuit



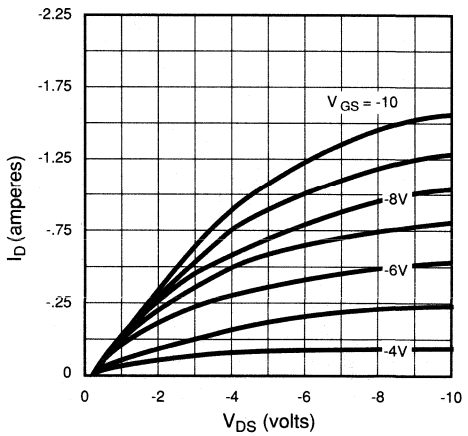


Typical Performance Curves

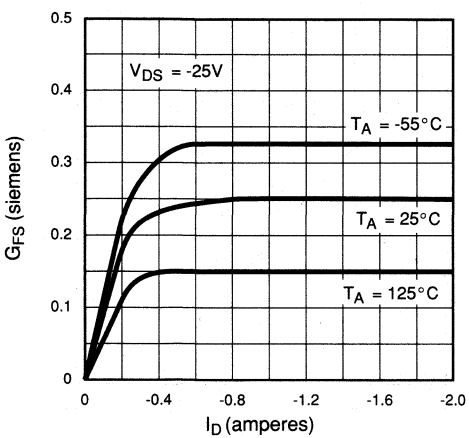
Output Characteristics



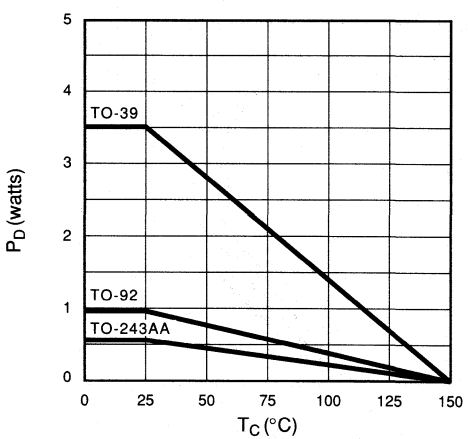
Saturation Characteristics



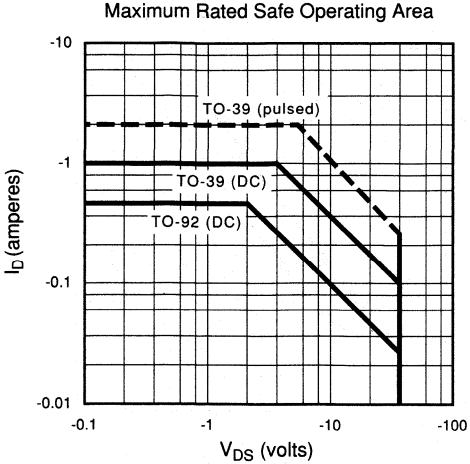
Transconductance vs. Drain Current



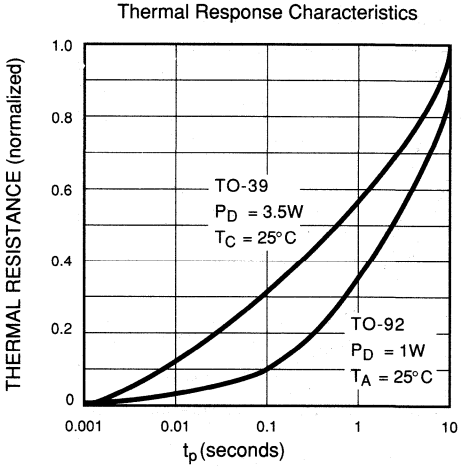
Power Dissipation vs. Case Temperature



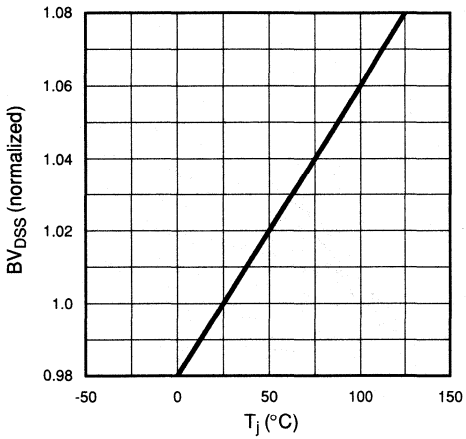
Maximum Rated Safe Operating Area



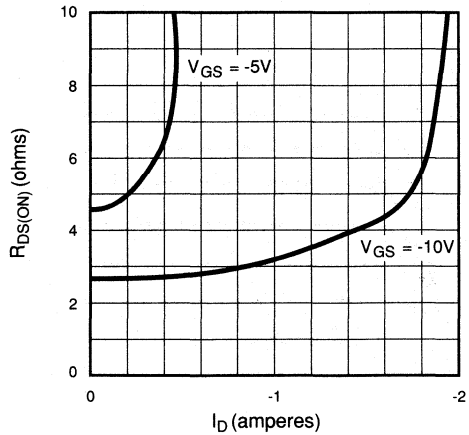
Thermal Response Characteristics



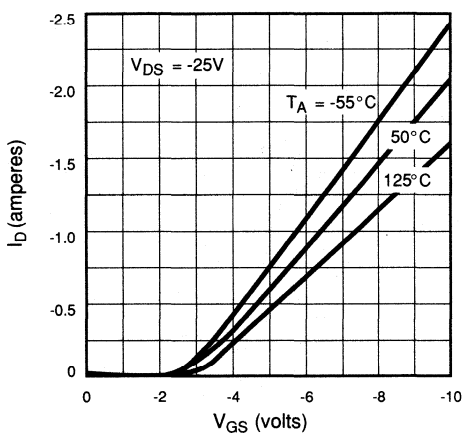
BV$_{DSS}$ Variation with Temperature



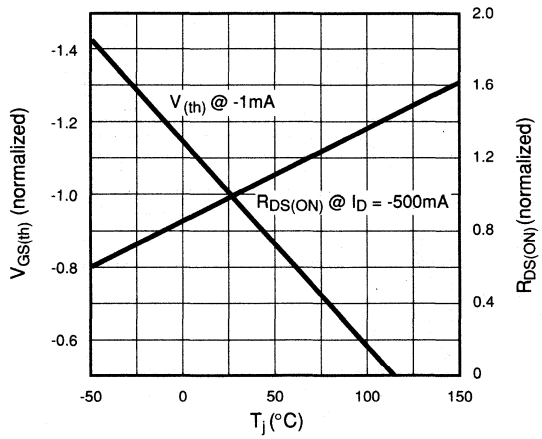
On-Resistance vs. Drain Current



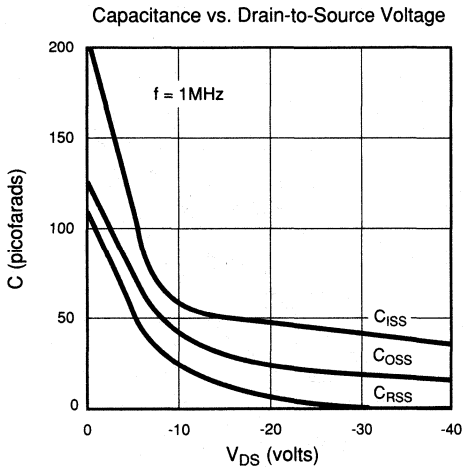
Transfer Characteristics



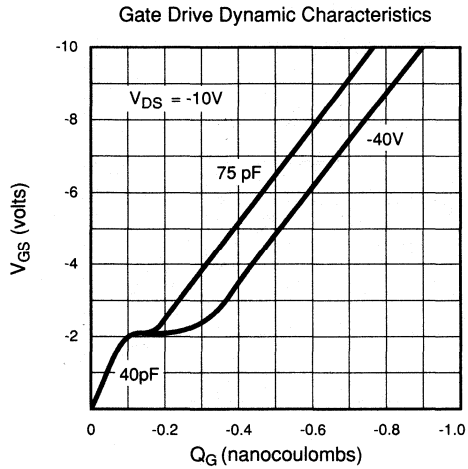
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package					
				TO-39	TO-92	TO-220	Quad P-DIP	Quad C-DIP*	DICE†
-60V	3.5Ω	-1.5A	-2.4V	TP0606N2	TP0606N3	TP0606N5	TP0606N6	TP0606N7	TP0606ND
-100V	3.5Ω	-1.5A	-2.4V	TP0610N2	TP0610N3	TP0610N5	—	—	TP0610ND

* 14 pin side brazed ceramic DIP
† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Low threshold — -2.4V max
- ☐ High input impedance
- ☐ Low input capacitance — 85 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

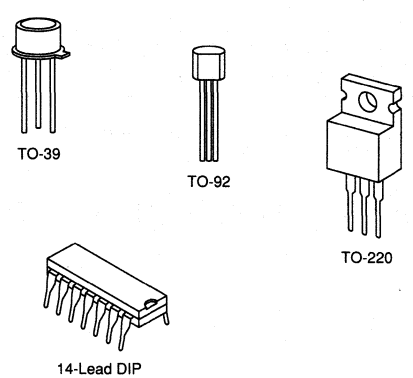
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Notes 1 and 2)



Note 1: See Package Outline section for discrete pinouts.
Note 2: See Array section for quad pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-39	-1.0A	-4.0A	6W	20	125	-0.8A	-4.0A
TO-92	-0.5A	-3.5A	1W	125	170	-0.4A	-3.5A
TO-220	-2.0A	-4.5A	45W	2.7	70	-2.0A	-4.5A
Plastic Dip	Refer to Arrays & Special Functions Section.						
Ceramic Dip							

* I_D (continuous) is limited by max rated T_j.

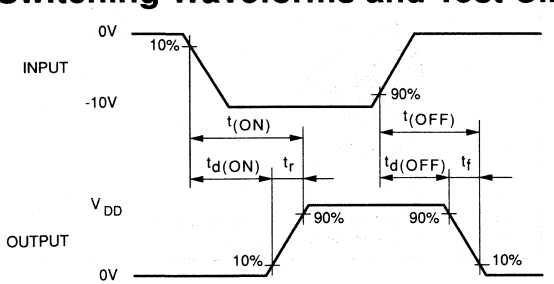
Electrical Characteristics (@ 25°C unless otherwise specified)

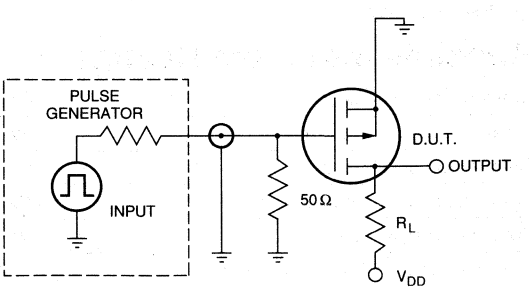
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TP0610	-100			V	V_{GS} = 0, I_D = -2.0mA
		TP0606	-60				
$V_{GS(th)}$	Gate Threshold Voltage		-1.0		-2.4	V	V_{GS} = V_{DS}, I_D = -1.0mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				-5.0	mV/°C	V_{GS} = V_{DS}, I_D = -1.0mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	µA	V_{GS} = 0, V_{DS} = Max Rating
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-0.4	-0.6		A	V_{GS} = -5V, V_{DS} = -25V
			-1.5	-2.5			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			5	7	Ω	V_{GS} = -5V, I_D = -250mA
				3	3.5		V_{GS} = -10V, I_D = -0.75A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				1.7	%/°C	V_{GS} = -10V, I_D = -0.75A
G_{FS}	Forward Transconductance		300			m℧	V_{DS} = -25V, I_D = -0.75A
C_{ISS}	Input Capacitance			85	150	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			50	85		
C_{RSS}	Reverse Transfer Capacitance			10	35		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = -25V, I_D = -1.0A, R_S = 50Ω
t_r	Rise Time				15		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				15		
V_{SD}	Diode Forward Voltage Drop				-1.8	V	V_{GS} = 0, I_{SD} = -1.0A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = -1.0A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

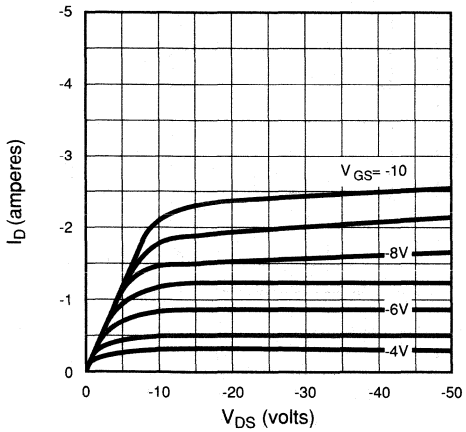
Switching Waveforms and Test Circuit



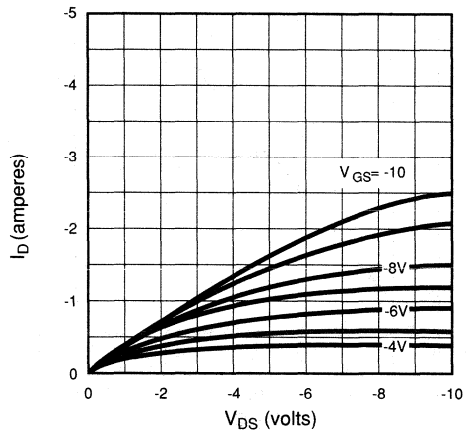


Typical Performance Curves

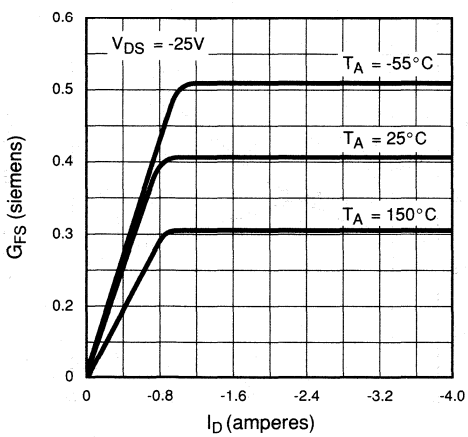
Output Characteristics



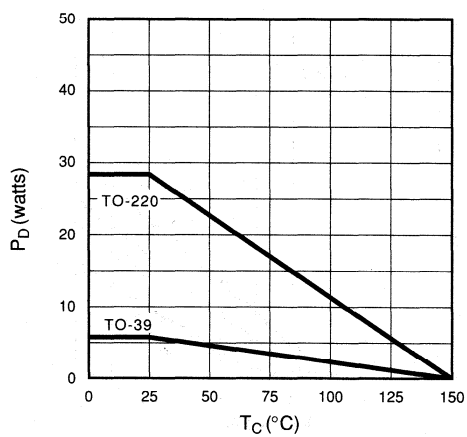
Saturation Characteristics



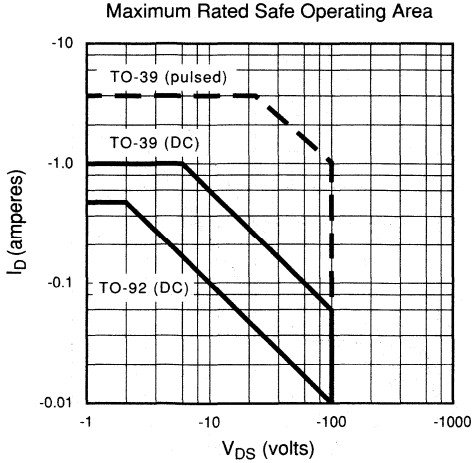
Transconductance vs. Drain Current



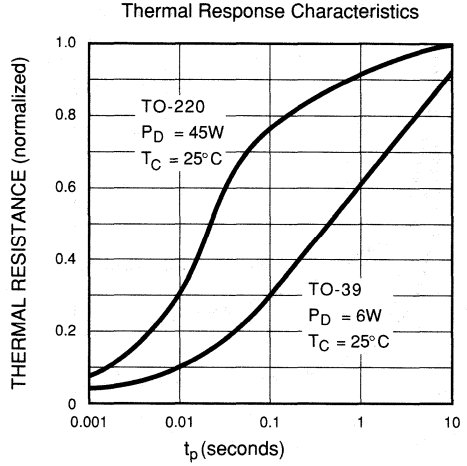
Power Dissipation vs. Case Temperature



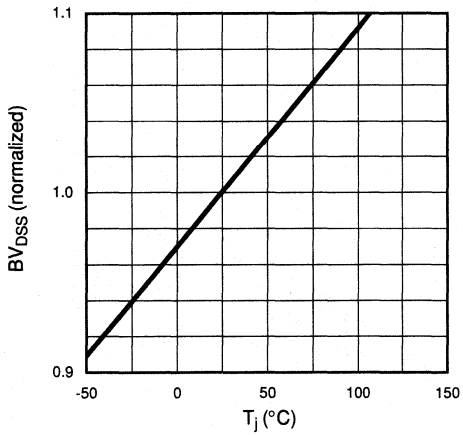
Maximum Rated Safe Operating Area



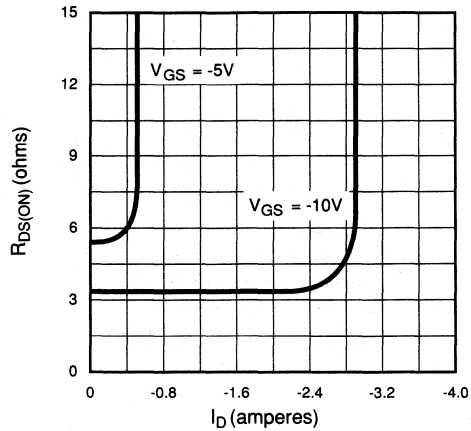
Thermal Response Characteristics



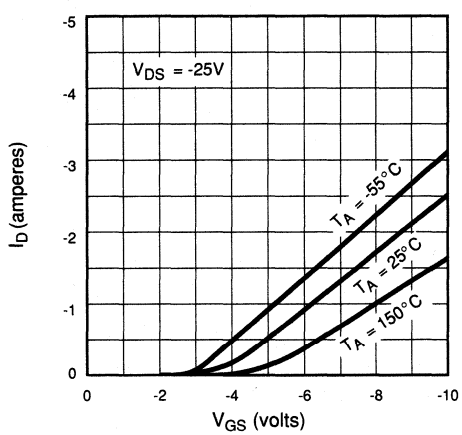
BV$_{DSS}$ Variation with Temperature



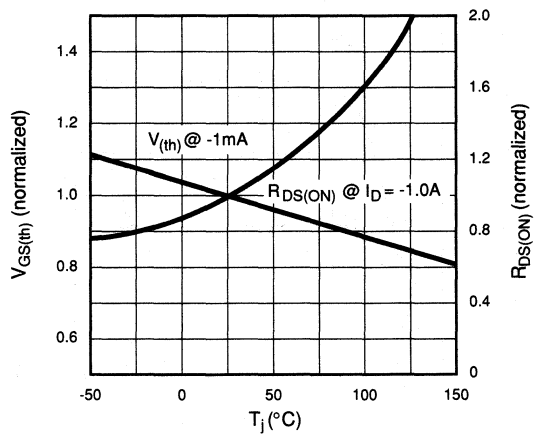
On-Resistance vs. Drain Current



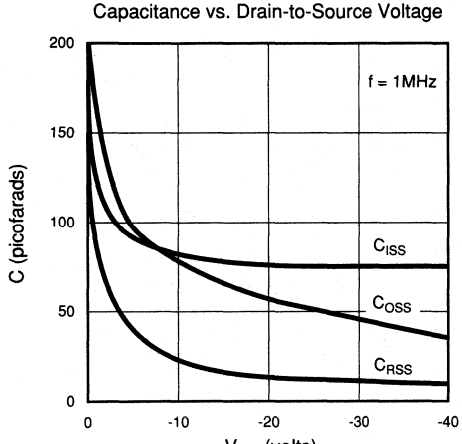
Transfer Characteristics



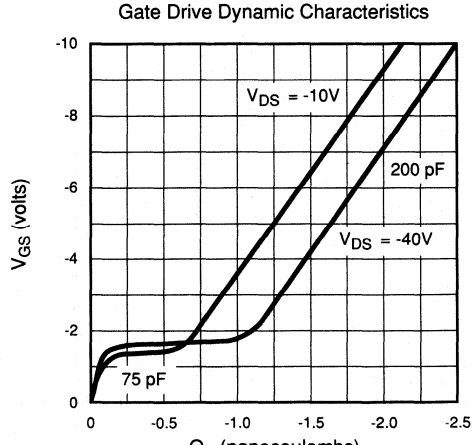
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package			
				TO-39	TO-92	TO-220	DICE†
-160V	12Ω	-0.75A	-2.4A	TP0616N2	TP0616N3	TP0616N5	TP0616ND
-200V	12Ω	-0.75A	-2.4A	TP0620N2	TP0620N3	TP0620N5	TP0620ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Low threshold — -2.4 V max
- ☐ High input impedance
- ☐ Low input capacitance — 85 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

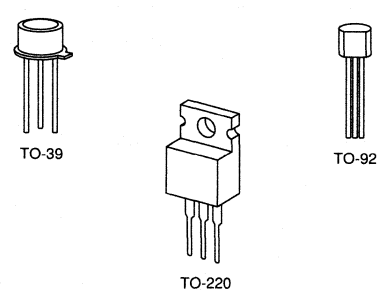
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



Note 1:See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-39	-0.6A	-1.5A	6W	20	125	-0.6A	-1.5A
TO-92	-0.4A	-0.8A	1W	125	170	-0.4A	-0.8A
TO-220	-1.4A	-2.5A	45W	2.7	70	-1.4A	-2.5A

* I_D (continuous) is limited by max rated T_j.

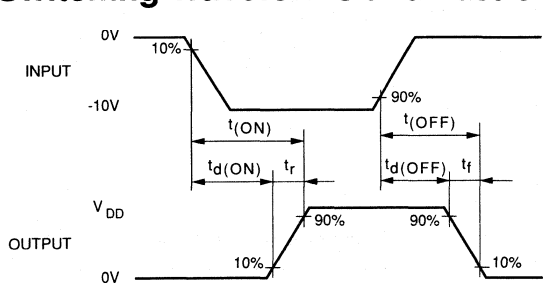
Electrical Characteristics (@ 25°C unless otherwise specified)

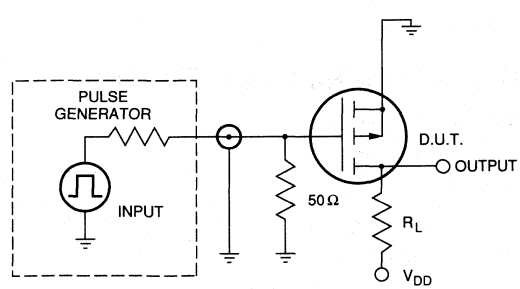
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TP0620	-200			V	V_{GS} = 0, I_D = -2.0mA
		TP0616	-160				
$V_{GS(th)}$	Gate Threshold Voltage		-1.0		-2.4	V	V_{GS} = V_{DS}, I_D = -1.0mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				-4.5	mV/°C	V_{GS} = V_{DS}, I_D = -1.0mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	µA	V_{GS} = 0, V_{DS} = Max Rating
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-0.25			A	V_{GS} = -5V, V_{DS} = -25V
			-0.75				V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			12	15	Ω	V_{GS} = -5V, I_D = -0.1A
				9	12		V_{GS} = -10V, I_D = -0.2A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				1.7	%/°C	V_{GS} = -10V, I_D = -0.2A
G_{FS}	Forward Transconductance		100			m℧	V_{DS} = -25V, I_D = -0.2A
C_{ISS}	Input Capacitance			85	150	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			30	85		
C_{RSS}	Reverse Transfer Capacitance			10	35		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = -25V, I_D = -1.0A, R_S = 50Ω
t_r	Rise Time				15		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				15		
V_{SD}	Diode Forward Voltage Drop				-1.8	V	V_{GS} = 0, I_{SD} = 0.5A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 0.5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

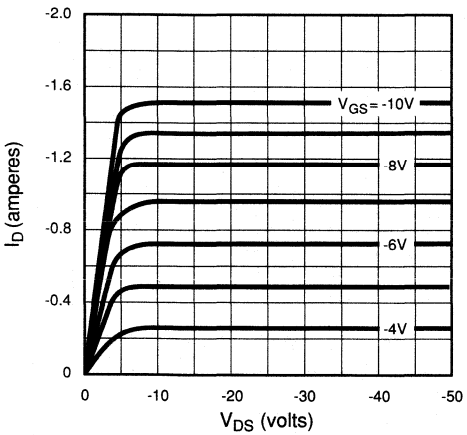
Switching Waveforms and Test Circuit



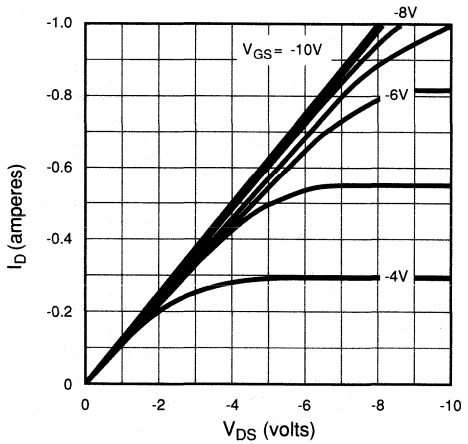


Typical Performance Curves

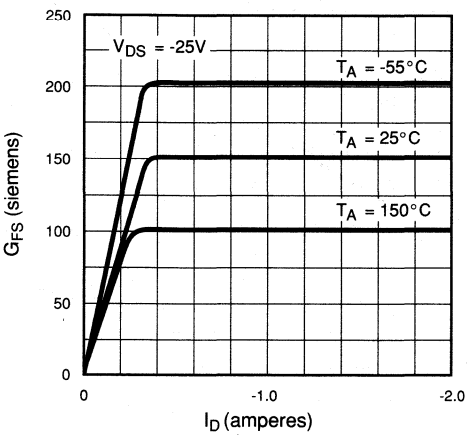
Output Characteristics



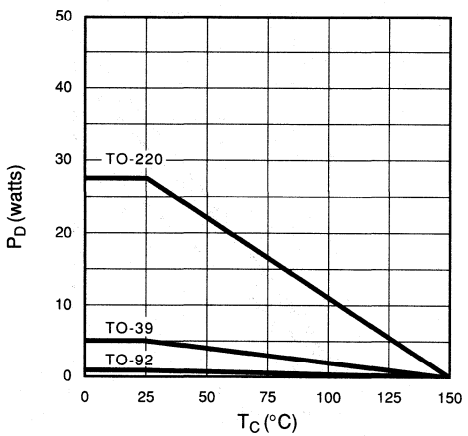
Saturation Characteristics



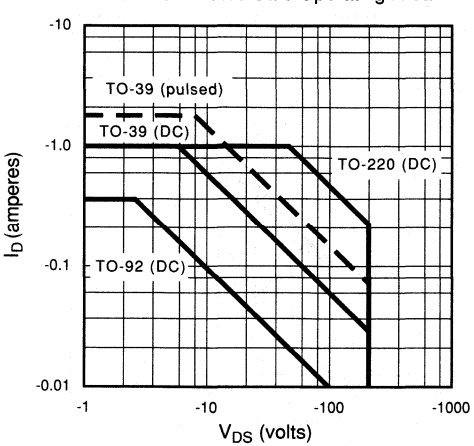
Transconductance vs. Drain Current



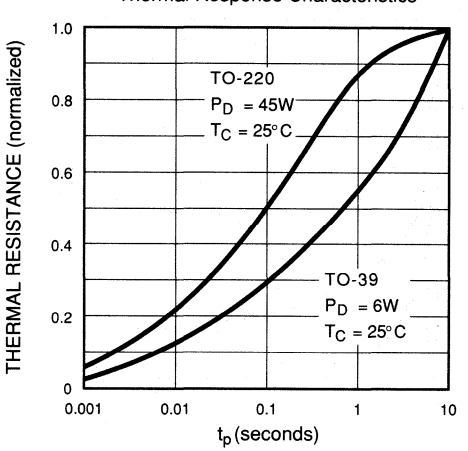
Power Dissipation vs. Case Temperature



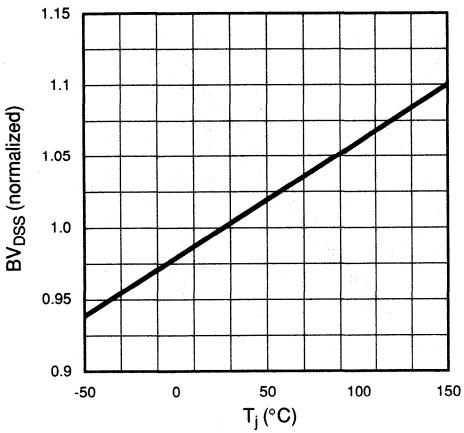
Maximum Rated Safe Operating Area



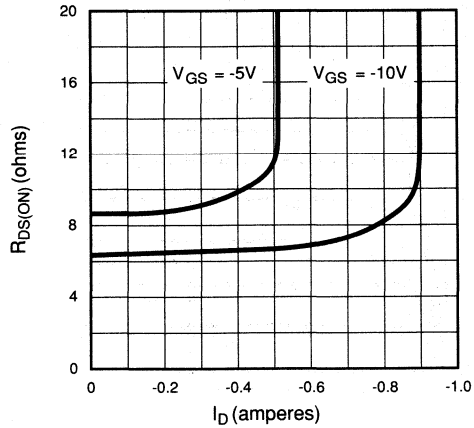
Thermal Response Characteristics



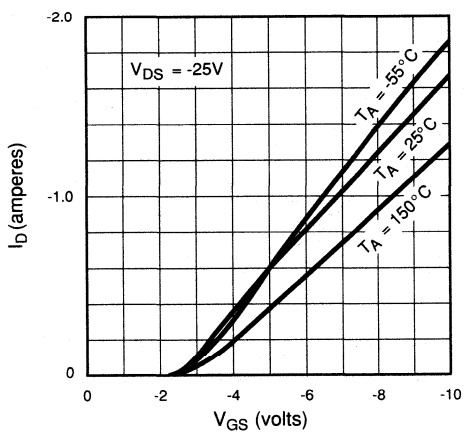
BV$_{DSS}$ Variation with Temperature



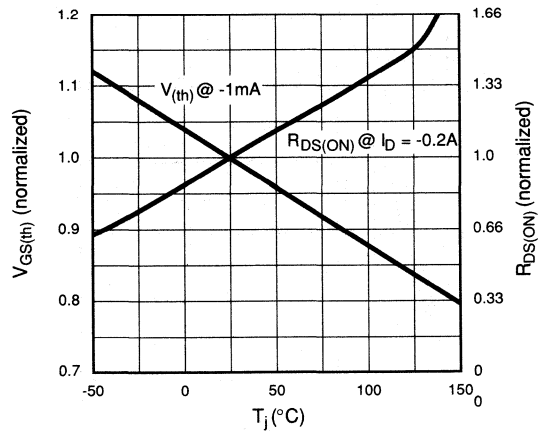
On-Resistance vs. Drain Current



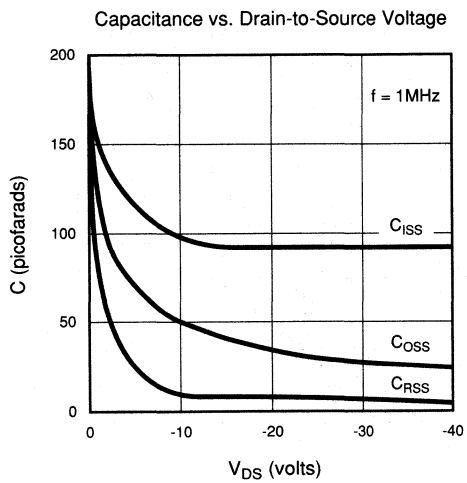
Transfer Characteristics



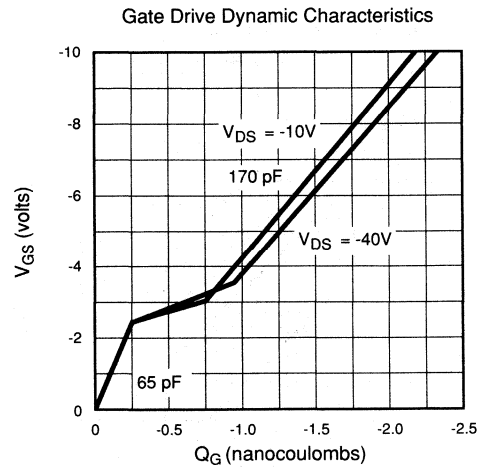
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package			
				TO-39	TO-92	SOW-20*	DICE†
-20V	2.0Ω	-2.0A	-2.4V	TP0602N2	TP0602N3	—	TP0602ND
-40V	2.0Ω	-2.0A	-2.4V	TP0604N2	TP0604N3	TP0604WG	TP0604ND

* Same as SO-20 with 300 mil wide body.
† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Low threshold — -2.4V max.
- ☐ High input impedance
- ☐ Low input capacitance — 95 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

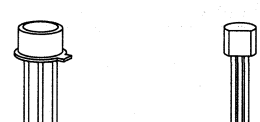
Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

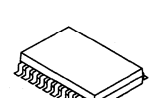
Package Options

(Notes 1 and 2)



TO-39

TO-92



SOW-20

Note 1: See Package Outline section for discrete pinouts.
Note 2: See Array section for quad pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-39	-2.0A	-4.8A	6W	20	125	-2.0A	-4.8A
TO-92	-0.75A	-4.2A	1W	125	170	-0.75A	-4.2A
SOW-20	Refer to Arrays & Special Functions Section						

* I_D (continuous) is limited by max rated T_j.

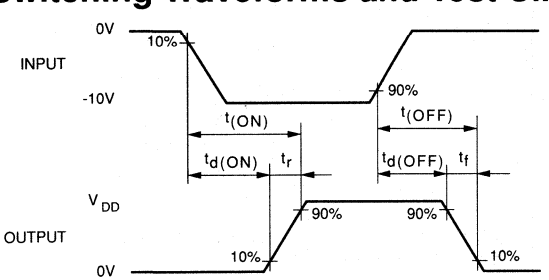
Electrical Characteristics (@ 25°C unless otherwise specified)

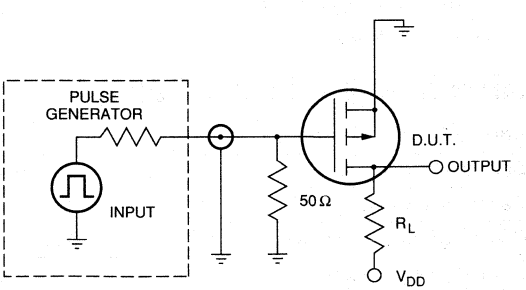
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TP0604	-40			V	V_{GS} = 0, I_D = -2.0mA
		TP0602	-20				
$V_{GS(th)}$	Gate Threshold Voltage		-1.0		-2.4	V	V_{GS} = V_{DS}, I_D = -1.0mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.0	-4.5	mV/°C	V_{GS} = V_{DS}, I_D = -1.0mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	µA	V_{GS} = 0, V_{DS} = Max Rating
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-0.4	-0.6		A	V_{GS} = -5V, V_{DS} = -25V
			-2.0	-3.3			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			2.0	3.5	Ω	V_{GS} = -5V, I_D = -250mA
				1.5	2.0		V_{GS} = -10V, I_D = -1.0A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.75	1.2	%/°C	V_{GS} = -10V, I_D = -1.0A
G_{FS}	Forward Transconductance		0.4	0.6		℧	V_{DS} = -25V, I_D = -1.0A
C_{ISS}	Input Capacitance			95	150	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			85	120		
C_{RSS}	Reverse Transfer Capacitance			40	60		
$t_{d(ON)}$	Turn-ON Delay Time			5	8	ns	V_{DD} = -25V, I_D = -1.0A, R_S = 50Ω
t_r	Rise Time			7	10		
$t_{d(OFF)}$	Turn-OFF Delay Time			10	15		
t_f	Fall Time			6	10		
V_{SD}	Diode Forward Voltage Drop			-1.3	-2.0	V	V_{GS} = 0, I_{SD} = -1.5A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = -1.5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

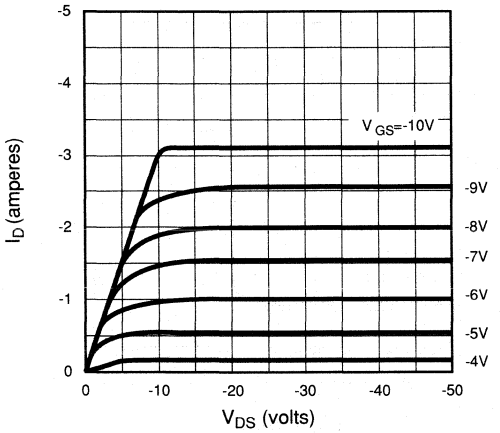
Switching Waveforms and Test Circuit



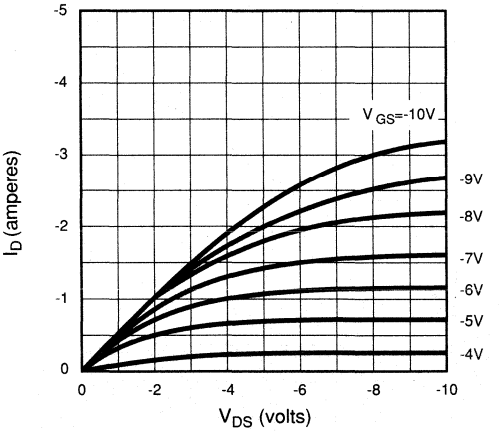


Typical Performance Curves

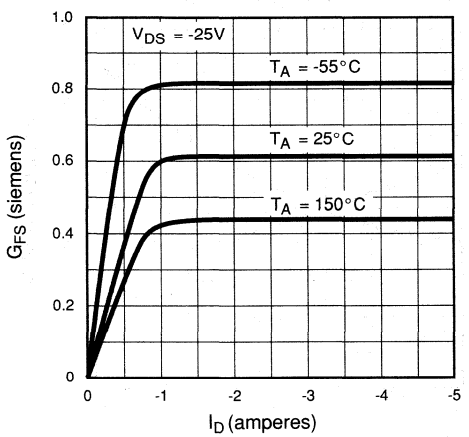
Output Characteristics



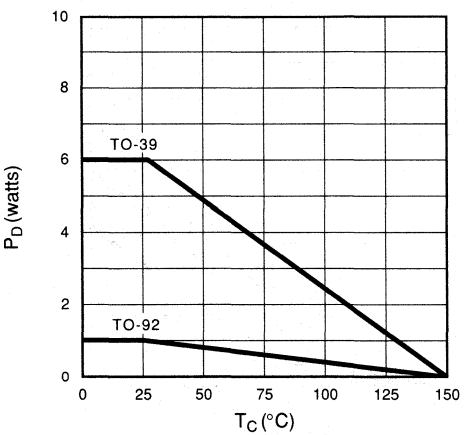
Saturation Characteristics



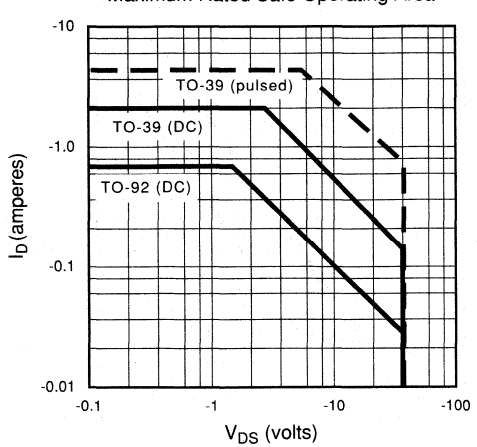
Transconductance vs. Drain Current



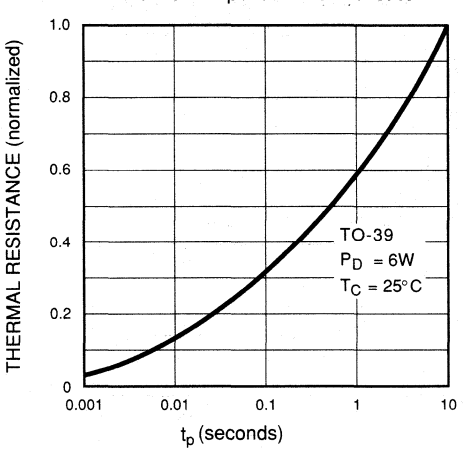
Power Dissipation vs. Case Temperature



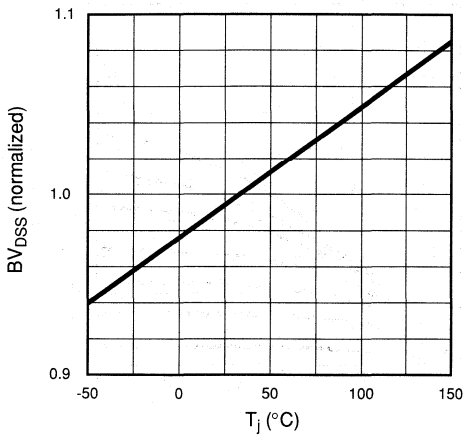
Maximum Rated Safe Operating Area



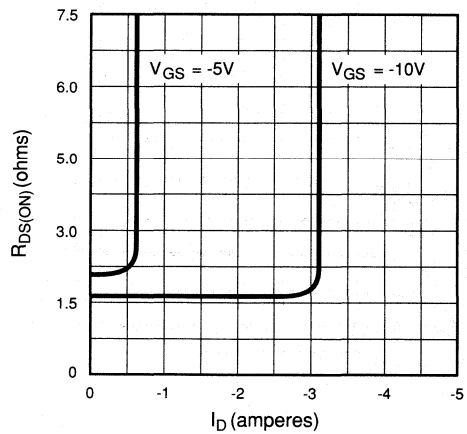
Thermal Response Characteristics



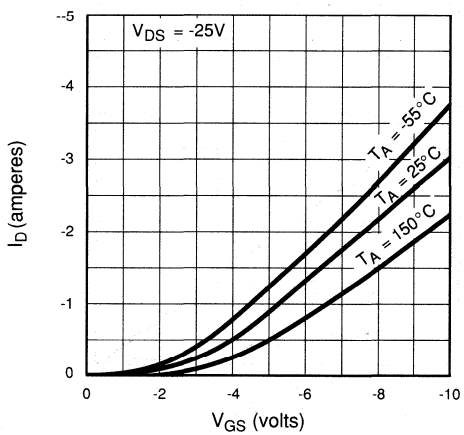
BV_{DSS} Variation with Temperature



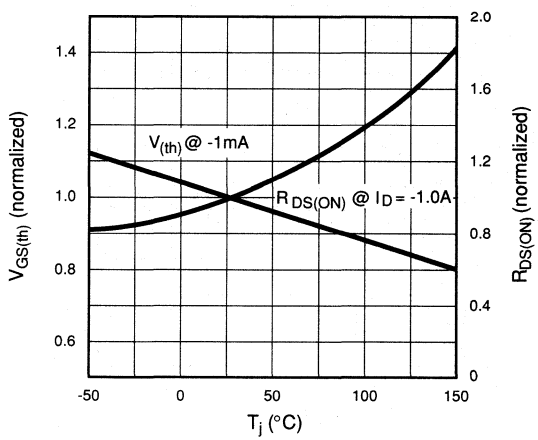
On-Resistance vs. Drain Current



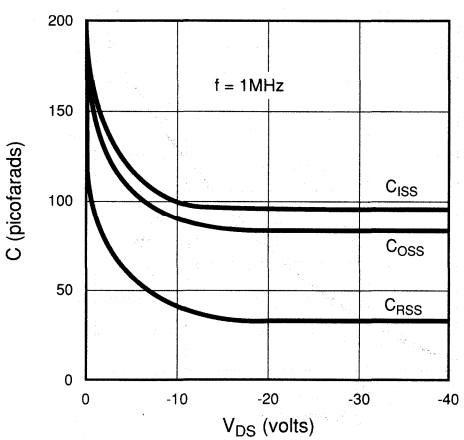
Transfer Characteristics



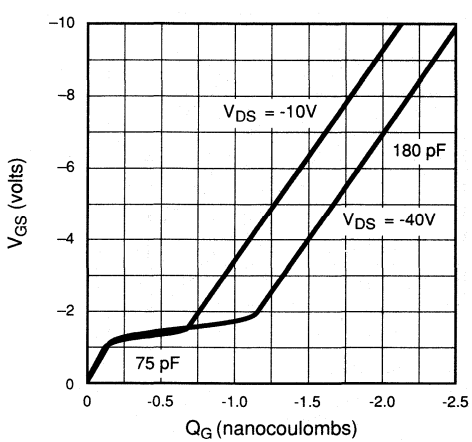
$V_{(th)}$ and R_{DS} Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	$V_{GS(th)}$ (max)	Order Number / Package	
				TO-92	DICE†
-20V	3.0Ω	-0.35A	-1.3V	TP0702N3	TP0702ND

† MIL visual screening available

Features

- ☐ Low threshold —1.0V max
- ☐ On resistance guaranteed at V_{GS} = 2, 3, and 5 volts
- ☐ High input impedance
- ☐ Low input capacitance —130 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage

Applications

- ☐ Logic level interface
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

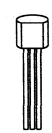
*Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-92	-0.35A	-0.40A	1W	125	170	-.035A	0.75A

* I_D (continuous) is limited by max rated T_j.

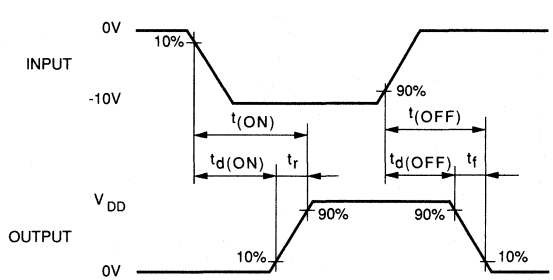
Electrical Characteristics (@ 25°C unless otherwise specified)

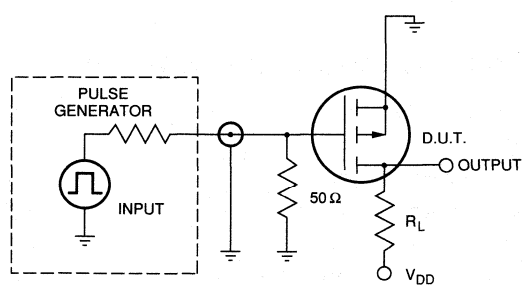
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	-20			V	V_{GS} = 0, I_D = -1mA
$V_{GS(th)}$	Gate Threshold Voltage	-0.7		-1.3	V	V_{GS} = V_{DS}, I_D = -1.0mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-4.5	mV/°C	V_{GS} = V_{DS}, I_D = -1.0mA
I_{GSS}	Gate Body Leakage			-100	nA	V_{GS} = ±20V, V_{DS} = 0V
I_{DSS}	Zero Gate Voltage Drain Current			-100	nA	V_{DS} = 20V, V_{GS} = 0V
				-100	µA	V_{DS} = 0.8 Max Rating, V_{GS} = 0V, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	-0.35			A	V_{GS} = V_{DS} = 5V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			10.0	Ω	V_{GS} = 2V, I_D = -30mA
				5.0		V_{GS} = 3V, I_D = -120mA
				3.0		V_{GS} = 5V, I_D = -250mA
G_{FS}	Forward Transconductance	80			m℧	V_{DS} = 5V, I_D = -250mA
C_{ISS}	Input Capacitance		130	200	pF	V_{GS} = 0V, V_{DS} = -20V, f =1MHz
C_{OSS}	Common Source Output Capacitance		70	125		
C_{RSS}	Reverse Transfer Capacitance		30	60		
$t_{d(ON)}$	Turn-ON Delay Time			20	ns	V_{DD} = 20V, I_D =-250mA, R_S = 50Ω
t_r	Rise Time			20		
$t_{d(OFF)}$	Turn-OFF Delay Time			30		
t_f	Fall Time			20		
V_{SD}	Diode Forward Voltage Drop			-1.0	V	V_{GS} = 0V, I_{SD} = -250mA

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwide stated. (Pulse test: 300 µs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$V_{GS(th)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
				TO-243AA*	DICE†
-60V	3.5Ω	-2.4V	-1.5A	—	TP2506ND
-100V	3.5Ω	-2.4V	-1.5A	TP2510N8	TP2510ND

* Same as SOT-89.
† MIL visual screening available.

Features

- ☐ Low threshold — -2.4V max.
- ☐ High input impedance
- ☐ Low input capacitance — 125 pF max
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

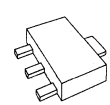
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-243AA
(SOT-89)

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-243AA	-0.28A	-1.5A	0.55W†	227†	—	-0.28A	-1.5A

* I_D (continuous) is limited by max rated T_j.
† Mounted on FR5 board, 25mm x 19mm x 1.57mm. Significant P_D increase possible on ceramic substrate.

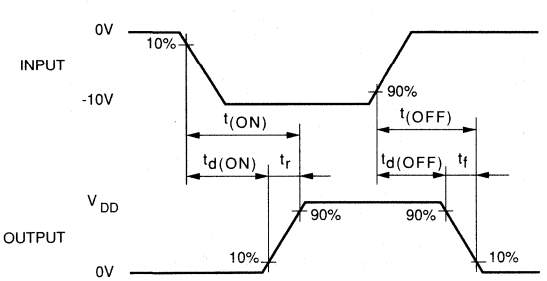
Electrical Characteristics (@ 25°C unless otherwise specified)

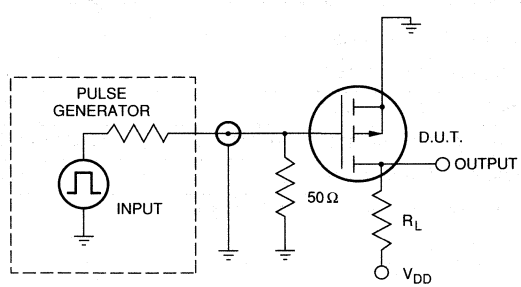
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TP2510	-100			V	V_{GS} = 0, I_D = -2mA
		TP2506	-60				
$V_{GS(th)}$	Gate Threshold Voltage		-1.0		-2.4	V	V_{GS} = V_{DS}, I_D= -1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				5.0	mV/°C	V_{GS} = V_{DS}, I_D= -1mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	µA	V_{GS} = 0, V_{DS} = Max Rating
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-0.4	-0.6		A	V_{GS} = -5V, V_{DS} = -25V
			-1.5	-2.5			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			5	7	Ω	V_{GS} = -5V, I_D = -250mA
				3	3.5		V_{GS} = -10V, I_D = -0.75A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				1.7	%/°C	V_{GS} = -10V, I_D = -0.75A
G_{FS}	Forward Transconductance		300			m℧	V_{DS} = -25V, I_D = -0.75A
C_{ISS}	Input Capacitance				125	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance				70		
C_{RSS}	Reverse Transfer Capacitance				25		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = -25V, I_D = -1.0A, R_S = 50Ω
t_r	Rise Time				15		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				15		
V_{SD}	Diode Forward Voltage Drop				-1.8	V	V_{GS} = 0, I_{SD} = -1.0A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = -1.0A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$V_{GS(th)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
				TO-243AA*	DICE†
-160V	12Ω	-2.4V	-0.75A	—	TP2516ND
-200V	12Ω	-2.4V	-0.75A	TP2520N8	TP2520ND

* Same as SOT-89.
† MIL visual screening available.

Features

- ☐ Low threshold — -2.4V max.
- ☐ High input impedance
- ☐ Low input capacitance — 125 pF max.
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

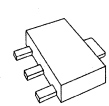
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-243AA
(SOT-89)

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-243AA	-0.15A	-0.75A	0.55W†	227†	—	-0.15A	-0.75A

* I_D (continuous) is limited by max rated T_j.
† Mounted on FR5 board, 25mm x 19mm x 1.57mm. Significant P_D increase possible on ceramic substrate.

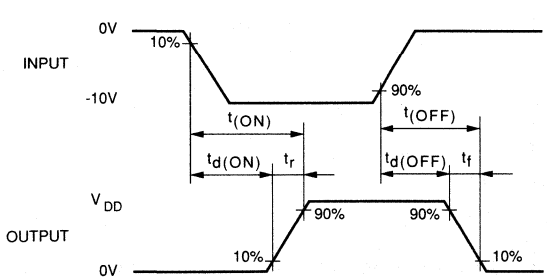
Electrical Characteristics (@ 25°C unless otherwise specified)

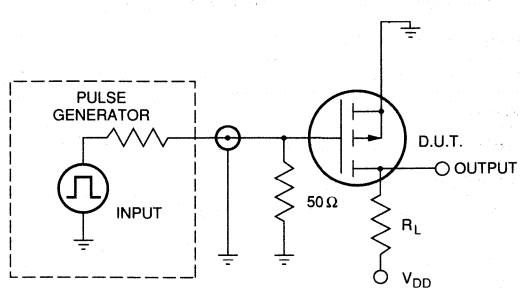
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TP2520	-200			V	V_{GS} = 0, I_D = -2mA
		TP2516	-160				
$V_{GS(th)}$	Gate Threshold Voltage		-1.0		-2.4	V	V_{GS} = V_{DS}, I_D= -1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				4.5	mV/°C	V_{GS} = V_{DS}, I_D= -1mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	µA	V_{GS} = 0, V_{DS} = Max Rating
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-0.25			A	V_{GS} = -4.5V, V_{DS} = -25V
			-0.75				V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			12	15	Ω	V_{GS} = -4.5V, I_D = -100mA
				9	12		V_{GS} = -10V, I_D = -200mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				1.7	%/°C	V_{GS} = -10V, I_D = -200mA
G_{FS}	Forward Transconductance		100			m ℧	V_{DS} = -25V, I_D = -200mA
C_{ISS}	Input Capacitance				125	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance				85		
C_{RSS}	Reverse Transfer Capacitance				35		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = -25V, I_D = -1.0A, R_S = 50Ω
t_r	Rise Time				15		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				15		
V_{SD}	Diode Forward Voltage Drop				-1.8	V	V_{GS} = 0, I_{SD} = -0.5A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = -0.5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$V_{GS(th)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
				TO-92	TO-243AA*	DICE†
-350V	25Ω	-2.4V	-0.4A	TP2535N3	—	TP2535ND
-400V	25Ω	-2.4V	-0.4A	TP2540N3	TP2540N8	TP2540ND

* Same as SOT-89.
† MIL visual screening available.

Features

- ☐ Low threshold — -2.4V max.
- ☐ High input impedance
- ☐ Low input capacitance — 125 pF typical
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

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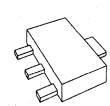
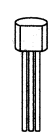
Package Options (Note 1)



TO-243AA
(SOT-89)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-92	-0.3A	-0.6A	1W	125	170	-03A	-0.6A
TO-243AA	-0.1A	-0.4A	0.55W†	227†	—	-0.1A	-0.4A

* I_D (continuous) is limited by max rated T_j.
† Mounted on FR5 board, 25mm x 19mm x 1.57mm. Significant P_D increase possible on ceramic substrate.

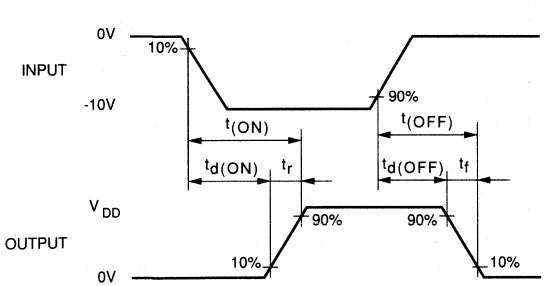
Electrical Characteristics (@ 25°C unless otherwise specified)

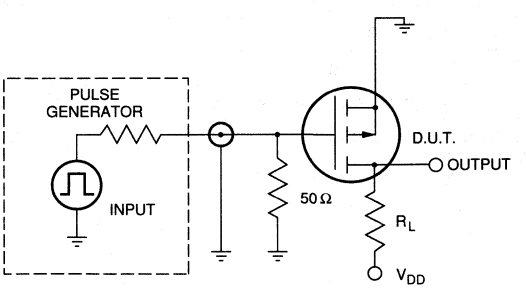
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TP2540	-400			V	V_{GS} = 0, I_D = -2mA
		TP2535	-350				
$V_{GS(th)}$	Gate Threshold Voltage		-1.0		-2.4	V	V_{GS} = V_{DS}, I_D= -1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				4.8	mV/°C	V_{GS} = V_{DS}, I_D= -1mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	µA	V_{GS} = 0, V_{DS} = Max Rating
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-200	-300		mA	V_{GS} = -4.5V, V_{DS} = -25V
			-400	-550			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			20	30	Ω	V_{GS} = -4.5V, I_D = -100mA
				19	25		V_{GS} = -10V, I_D = -100mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				0.75	%/°C	V_{GS} = -10V, I_D = -100mA
G_{FS}	Forward Transconductance		100			m℧	V_{DS} = -25V, I_D = -100mA
C_{ISS}	Input Capacitance				125	pF	V_{GS} = 0, V_{DS} = -25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance				70		
C_{RSS}	Reverse Transfer Capacitance				25		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = -25V, I_D = -100mA, R_S = 50Ω
t_r	Rise Time				10		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				10		
V_{SD}	Diode Forward Voltage Drop				-1.8	V	V_{GS} = 0, I_{SD} = -100mA
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = -100mA

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

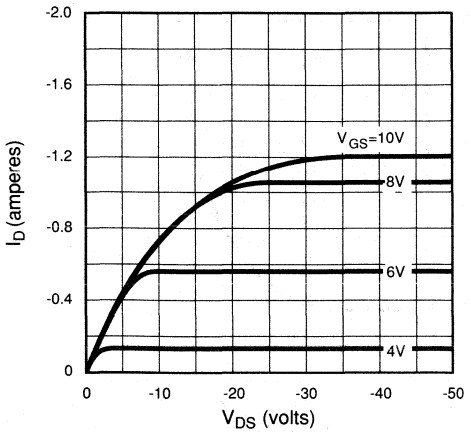
Switching Waveforms and Test Circuit



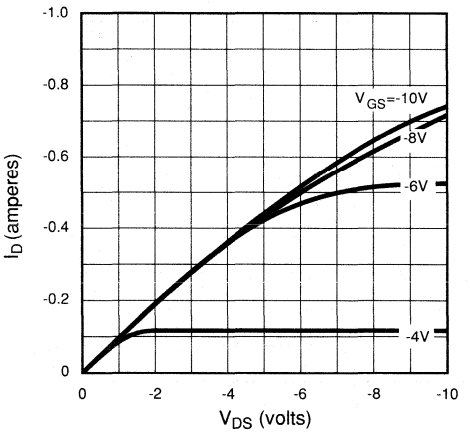


Typical Performance Curves

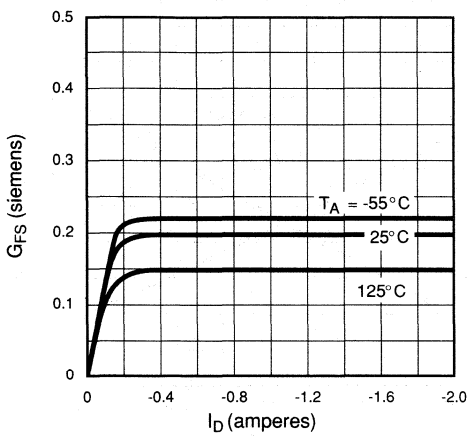
Output Characteristics



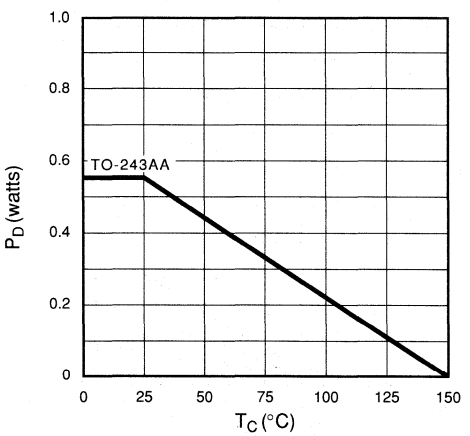
Saturation Characteristics



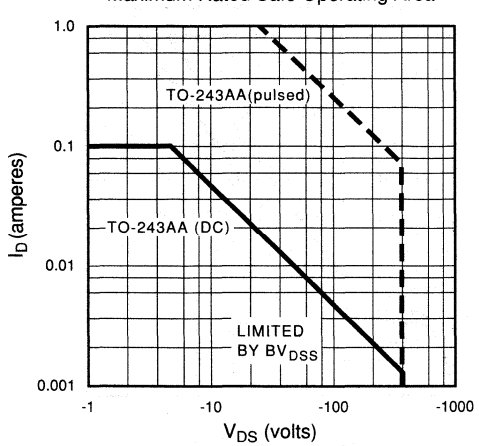
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

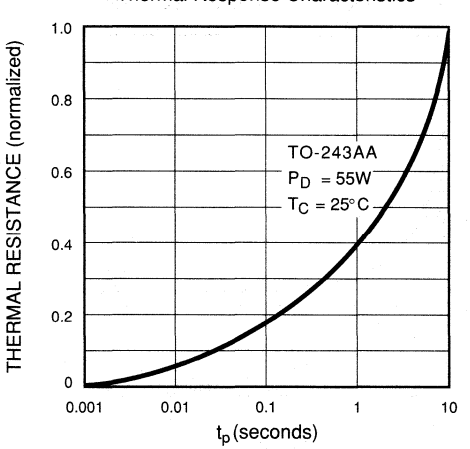


Maximum Rated Safe Operating Area

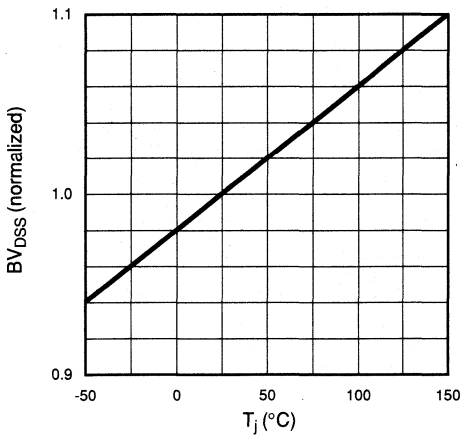


Pulsed Condition: 300 µs; 20% Duty Cycle

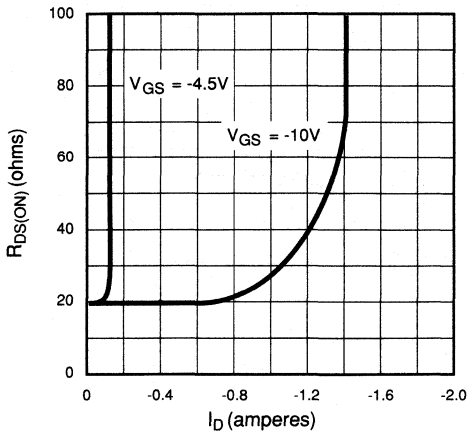
Thermal Response Characteristics



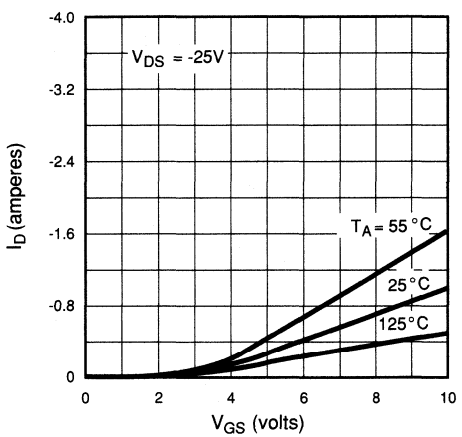
BV$_{DSS}$ Variation with Temperature



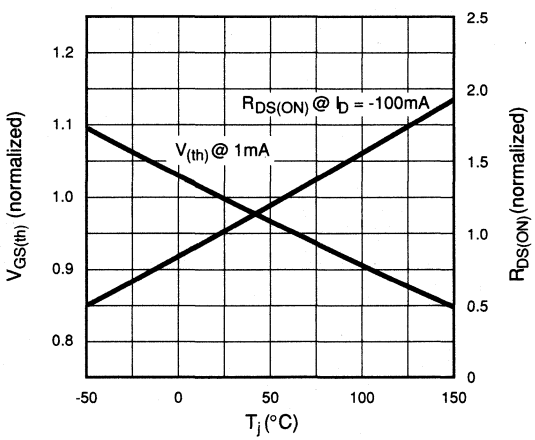
On-Resistance vs. Drain Current



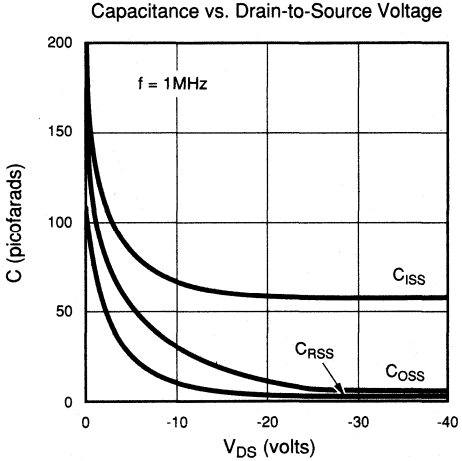
Transfer Characteristics



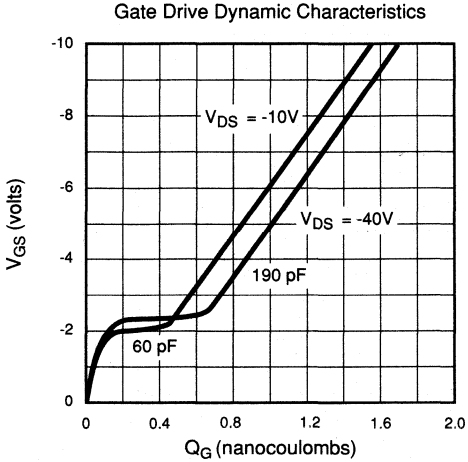
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$V_{GS(th)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
				TO-243AA*	DICE†
-20V	2.0Ω	-2.4V	-2.0A	TP2502N8	TP2502ND

* Same as SOT-89.
† MIL visual screening available.

Features

- ☐ Low threshold — -2.4V max.
- ☐ High input impedance
- ☐ Low input capacitance — 125 pF max.
- ☐ Fast switching speeds
- ☐ Low on resistance
- ☐ Free from secondary breakdown
- ☐ Low input and output leakage
- ☐ Complementary N- and P-channel devices

Applications

- ☐ Logic level interface – ideal for TTL and CMOS
- ☐ Solid state relays
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Analog switches
- ☐ General purpose line driver
- ☐ Telecom switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

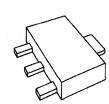
* Distance of 1.6 mm from case for 10 seconds.

Low Threshold DMOS Technology

These low threshold enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where very low threshold voltage, high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-243AA
(SOT-89)

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-243AA	-0.37A	-2.0A	0.55W†	227†	—	-0.37A	-2.0A

* I_D (continuous) is limited by max rated T_j.
† Mounted on FR5 board, 25mm x 19mm x 1.57mm. Significant P_D increase possible on ceramic substrate.

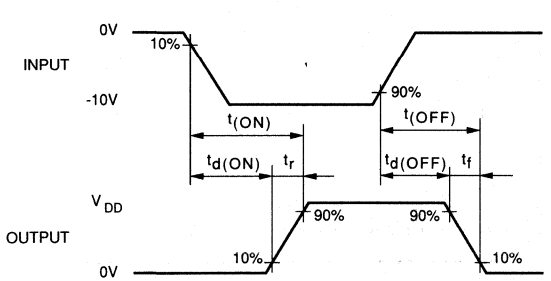
Electrical Characteristics (@ 25°C unless otherwise specified)

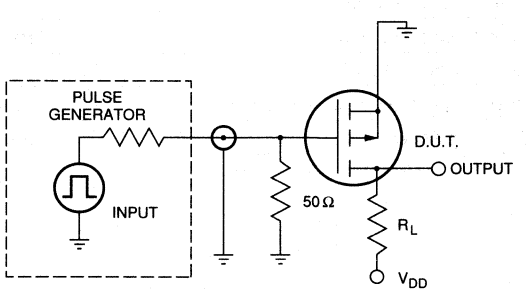
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TP2504	-40			V	V_{GS} = 0, I_D = -2mA
		TP2502	-20				
$V_{GS(th)}$	Gate Threshold Voltage		-1.0		-2.4	V	V_{GS} = V_{DS}, I_D= -1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			3.0	4.5	mV/°C	V_{GS} = V_{DS}, I_D= -1mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	µA	V_{GS} = 0, V_{DS} = Max Rating
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-0.4	-0.7		A	V_{GS} = -5V, V_{DS} = -15V
			-2.0	-3.3			V_{GS} = -10V, V_{DS} = -15V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			2.0	3.5	Ω	V_{GS} = -5V, I_D = -250mA
				1.5	2.0		V_{GS} = -10V, I_D = -1A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.75	1.2	%/°C	V_{GS} = -10V, I_D = -1A
G_{FS}	Forward Transconductance		0.4	0.65		℧	V_{DS} = -15V, I_D = -1A
C_{ISS}	Input Capacitance				125	pF	V_{GS} = 0, V_{DS} = -15V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance				70		
C_{RSS}	Reverse Transfer Capacitance				25		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = -15V, I_D = -1.0A, R_S = 50Ω
t_r	Rise Time				10		
$t_{d(OFF)}$	Turn-OFF Delay Time				15		
t_f	Fall Time				10		
V_{SD}	Diode Forward Voltage Drop			1.3	2.0	V	V_{GS} = 0, I_{SD} = -1.5A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = -1.5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FET

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package
			TO-39
35V	1.8Ω	1.5A	2N6659

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	±40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

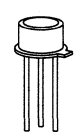
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-39

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W
TO-39	1.4A	3A	6.25W	170	20

* I_D (continuous) is limited by max rated T_j.

Electrical Characteristics (@ 25°C unless otherwise specified)

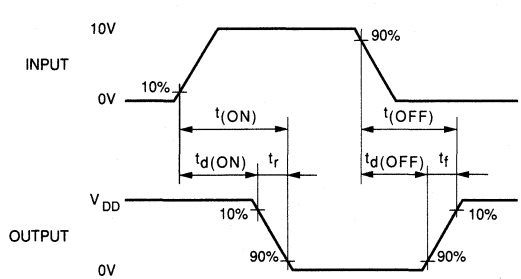
(Notes 1 and 2)

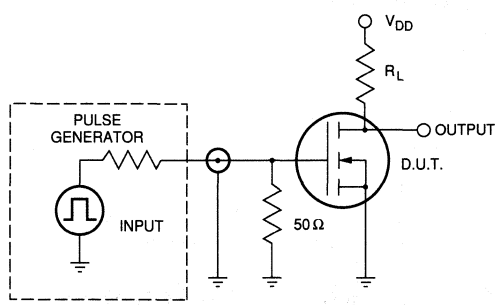
Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	35			V	I_D = 10μA, V_{GS} = 0
$V_{GS(th)}$	Gate Threshold Voltage	0.8		2.0	V	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage			100	nA	V_{GS} = ±15V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			10	μA	V_{GS} = 0, V_{DS} = Max Rating
				500		V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	1.5			A	V_{GS} = -10V, V_{DS} ≥ $2V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			5	Ω	V_{GS} = 5V, I_D = 3A
				1.8		V_{GS} = 10V, I_D = 1A
G_{FS}	Forward Transconductance	170			m℧	V_{DS}= 25V, I_D = 0.5A
C_{ISS}	Input Capacitance			50	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			40		
C_{RSS}	Reverse Transfer Capacitance			10		
$t_{d(ON)}$	Turn-ON Delay Time			10	ns	V_{DD} = 25V, I_D = 1A, R_S = 50Ω
$t_{d(OFF)}$	Turn-OFF Delay Time			10		
V_{SD}	Diode Forward Voltage Drop		1.2	1.8	V	I_{SD} = -1.4A, V_{GS} = 0

Notes:

1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300μs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package
			TO-39
60V	3.0Ω	1.5A	2N6660
90V	4.0Ω	1.5A	2N6661

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 30V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

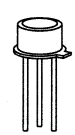
Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options

(Note 1)



TO-39

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
2N6660	1.1A	3A	6.25W	20	125	2.5A	5.0A
2N6661	0.9A	3A	6.25W	20	125	2.5A	5.0A

* I_D (continuous) is limited by max rated T_j.

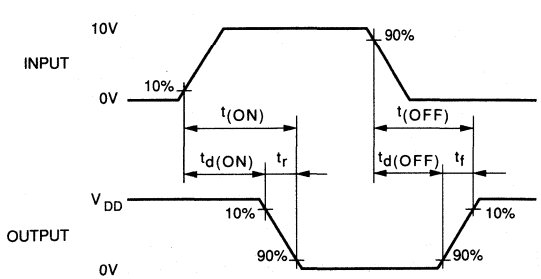
Electrical Characteristics (@ 25°C unless otherwise specified)

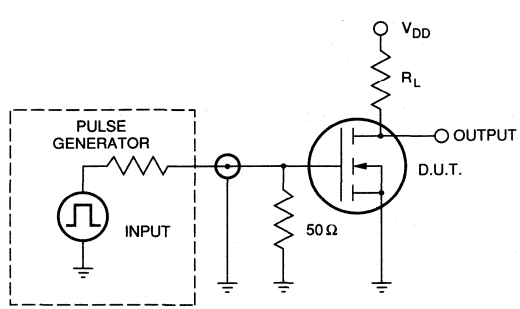
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	2N6660	60			V	V_{GS} = 0, I_D = 10μA
		2N6661	90				
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2.0	V	V_{GS} = V_{DS}, I_D = 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.8	-5.5	mV/°C	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage				100	μA	V_{GS} = ± 20V, V_{DS} = 0
					500		V_{GS} = 0, V_{DS} = 0, T_A = 125°C
I_{DSS}	Zero Gate Voltage Drain Current				10	μA	V_{GS} = 0, V_{DS} = 0.8 Max Rating
					500		V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		1.5			A	V_{GS} = 10, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	All			5.0	Ω	V_{GS} = 5V, I_D = 0.3A
		2N6660			3.0		V_{GS} = 10V, I_D = 1A
		2N6661			4.0		V_{GS} = 10V, I_D = 1A
G_{FS}	Forward Transconductance		170			m	V_{DS} = 25V, I_D = .05A
C_{ISS}	Input Capacitance				50	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance				40		
C_{RSS}	Reverse Transfer Capacitance				10		
$t_{(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = 25V, R_L = 23Ω, R_S = 25Ω
$t_{(OFF)}$	Turn-OFF Delay Time				10		
V_{SD}	Diode Forward Voltage Drop			1.2		V	V_{GS} = 0, I_{SD} = 1A
t_{rr}	Reverse Recovery Time			350		ns	V_{GS} = 0, I_{SD} = 1A

Notes:
1: All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2: All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FET

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package
			TO-92
60V	5Ω	75mA	2N7000

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

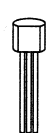
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W
TO-92	200mA	500mA	400mW	312.5	40

* I_D (continuous) is limited by max rated T_j.

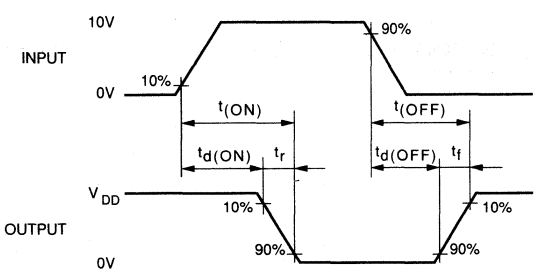
Electrical Characteristics (@ 25°C unless otherwise specified)

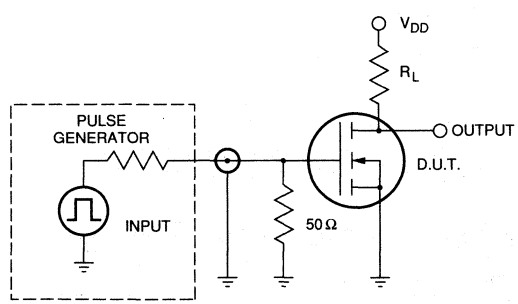
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	60			V	I_D = 10μA, V_{GS} = 0
$V_{GS(th)}$	Gate Threshold Voltage	0.8		3.0	V	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage			10	nA	V_{GS} = ±15V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			1	μA	V_{GS} = 0, V_{DS} = 48V
				1	mA	V_{GS} = 0, V_{DS} = 48V T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	75			mA	V_{GS} = 4.5V, V_{DS} 10V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			5	Ω	V_{GS} = 10V, I_D = 0.5V
G_{FS}	Forward Transconductance	100			m℧	V_{DS} = 10V, I_D = 0.2A
C_{ISS}	Input Capacitance			60	pF	V_{GS} = 0V, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			25		
C_{RSS}	Reverse Transfer Capacitance			5		
$t_{d(ON)}$	Turn-ON Delay Time			10	ns	
$t_{d(OFF)}$	Turn-OFF Delay Time			10		
V_{SD}	Diode Forward Voltage Drop		-0.85		V	I_{SD} = -0.2A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300μs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FET

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package
			TO-92
240V	45Ω	150mA	2N7007

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	±40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

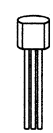
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W
TO-92	65mA	260mA	400mW	312.5	40

* I_D (continuous) is limited by max rated T_j.

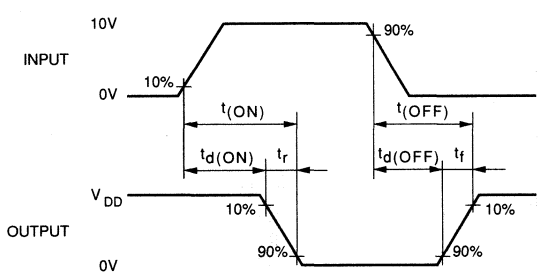
Electrical Characteristics (@ 25°C unless otherwise specified)

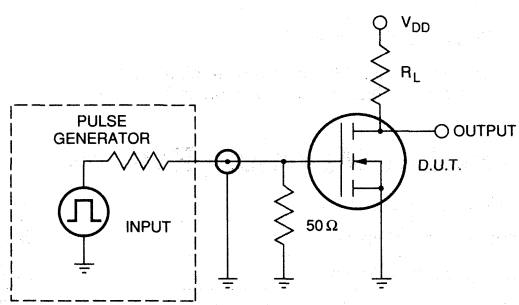
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	240			V	I_D = 100μA, V_{GS} = 0
$V_{GS(th)}$	Gate Threshold Voltage	1		2.5	V	V_{GS} = V_{DS}, I_D = 250μA
I_{GSS}	Gate Body Leakage			10	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			100	nA	V_{GS} = 0, V_{DS} = 120V
				1	μA	V_{GS} = 0, V_{DS} = 120V T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	50			mA	V_{GS} = 4.5V, V_{DS} ≥ 2$V_{DS(ON)}$
		150				V_{GS} = 10V, V_{DS} ≥ 2$V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance		45		Ω	V_{GS} = 4.5V, I_D = 20mA
				45		V_{GS} = 10V, I_D = 50mA
G_{FS}	Forward Transconductance	80			m℧	V_{DS} V_{DS} ≥ 2$V_{DS(ON)}$, I_D = 50mA
C_{ISS}	Input Capacitance			30	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			15		
C_{RSS}	Reverse Transfer Capacitance			10		
$t_{d(ON)}$	Turn-ON Delay Time			30	ns	V_{DD} = 60V, I_D = 50 mA, R_S = 50Ω
$t_{d(OFF)}$	Turn-OFF Delay Time			20		
V_{SD}	Diode Forward Voltage Drop			-1.2	V	I_{SD} =- 65mA, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300μs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package
			TO-92
60V	7.5Ω	500mA	2N7008

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

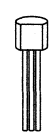
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W
TO-92	150mA	1A	400mW	312.5	40

* I_D (continuous) is limited by max rated T_j.

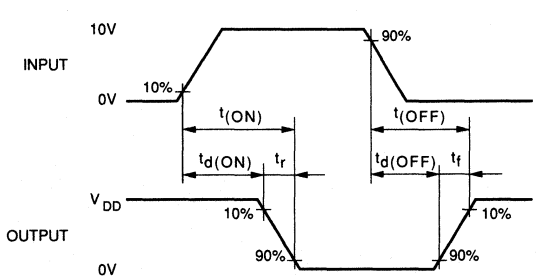
Electrical Characteristics (@ 25°C unless otherwise specified)

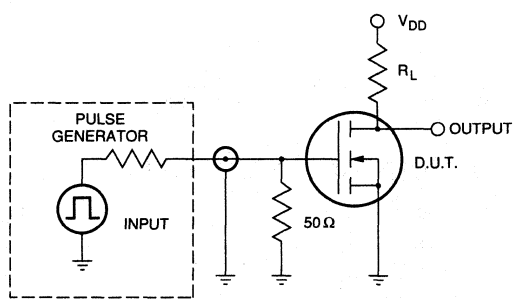
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	60			V	I_D = -10μA, V_{GS} = 0
$V_{GS(th)}$	Gate Threshold Voltage	1		2.5	V	V_{GS} = V_{DS}, I_D = 250μA
I_{GSS}	Gate Body Leakage			100	nA	V_{GS} = ±30V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			1	μA	V_{GS} = 0, V_{DS} = 50V
				500	μA	V_{GS} = 0, V_{DS} = 50V, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	500			mA	V_{GS} = 10V, V_{DS} ≥ $2V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resostance			7.5	Ω	V_{GS} = 5V, I_D = 50mA
				7.5		V_{GS} = 10V, I_D = 500mA
G_{FS}	Forward Transconductance	80			m℧	V_{DS} = 10V, I_D = 0.2A
C_{ISS}	Input Capacitance			50	pF	V_{GS} = 0V, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			25		
C_{RSS}	Reverse Transfer Capacitance			5		
$td_{(ON)}$	Turn-ON Delay Time			20	ns	V_{DD} = 30V, I_D =200 mA, R_S = 50Ω
$td_{(OFF)}$	Turn-OFF Delay Time			20		
V_{SD}	Diode Forward Voltage Drop			-1.5	V	I_{SD} = -150mA, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300μs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package						
			TO-39	TO-52	TO-92	TO-220	Quad P-DIP	Quad C-DIP*	DICE†
40V	3Ω	2.0A	VN0104N2	VN0104N9	VN0104N3	VN0104N5	VN0104N6	VN0104N7	VN0104ND
60V	3Ω	2.0A	VN0106N2	VN0106N9	VN0106N3	VN0106N5	VN0106N6	VN0106N7	VN0106ND
90V	3Ω	2.0A	VN0109N2	VN0109N9	VN0109N3	VN0109N5	—	—	VN0109ND

* 14 pin side brazed ceramic DIP
† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

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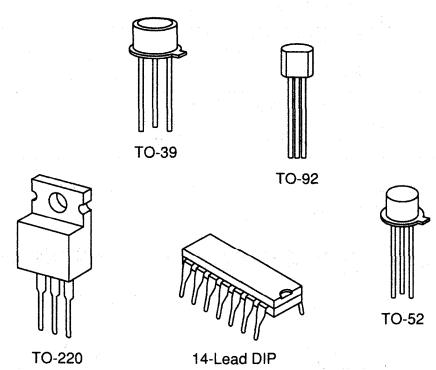
Package Options (Notes 1 and 2)



Note 1: See package outline section for discrete pinout.
Note 2: See array section for quad pinout.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	0.8A	2.5A	3.5W	125	35	0.08A	2.5A
TO-52	0.5A	2.0A	1.0W	170	125	0.5A	2.0A
TO-92	0.5A	2.0A	1.0W	170	125	0.5A	2.0A
TO-220	1.5A	2.5A	15.0W	70	8	1.5A	2.5A
Plastic DIP Ceramic DIP	See DMOS Arrays & Special Functions section						

* I_D (continuous) is limited by max rated T_j.

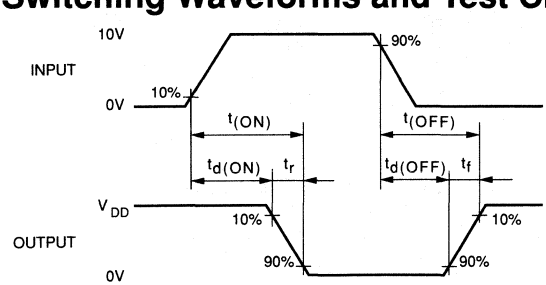
Electrical Characteristics (@ 25°C unless otherwise specified)

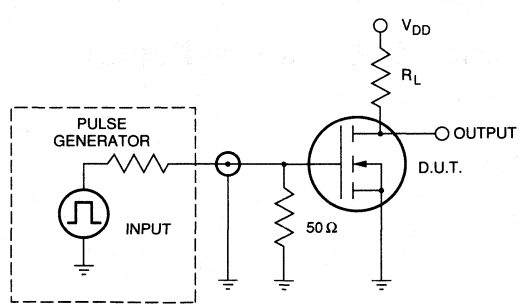
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN0109	90			V	V_{GS} = 0, I_D = 1mA
		VN0106	60				
		VN0104	40				
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2.4	V	V_{GS} = V_{DS}, I_D = 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.8	-5.5	mV/°C	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage			0.1	100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				1	µA	V_{GS} = 0, V_{DS} = Max Rating
					100		V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		0.5	1.0		A	V_{GS} = 5V, V_{DS} = 25V
			2.0	2.50			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			4.50	5	Ω	V_{GS} = 5V, I_D = 250mA
				2	3		V_{GS} = 10V, I_D = 1A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.70	1	%/°C	V_{GS} = 10V, I_D = 1A
G_{FS}	Forward Transconductance		300	400		m℧	V_{DS} = 25V, I_D = 0.5A
C_{ISS}	Input Capacitance			45	60	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			20	25		
C_{RSS}	Reverse Transfer Capacitance			2	5		
$t_{d(ON)}$	Turn-ON Delay Time			3	5	ns	V_{DD} = 25V I_D = 1A R_S = 50Ω
t_r	Rise Time			5	8		
$t_{d(OFF)}$	Turn-OFF Delay Time			6	9		
t_f	Fall Time			5	8		
V_{SD}	Diode Forward Voltage Drop			1.2	1.8	V	V_{GS} = 0, I_{SD} =1.0A
t_{rr}	Reverse Recovery Time			400		ns	V_{GS} = 0, I_{SD} =1.0A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

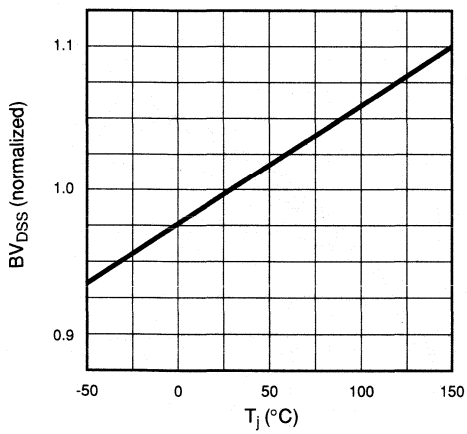
Switching Waveforms and Test Circuit



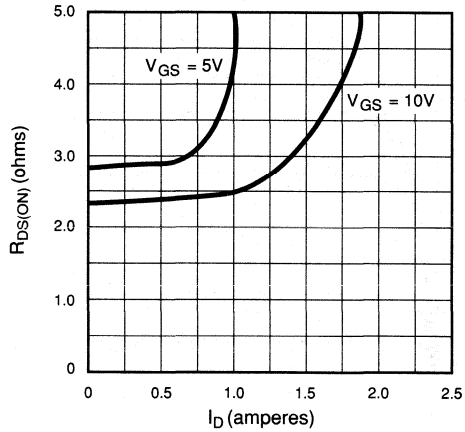


Typical Performance Curves

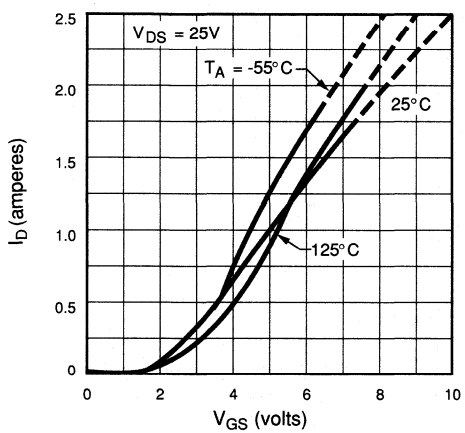
BV_{DSS} Variation with Temperature



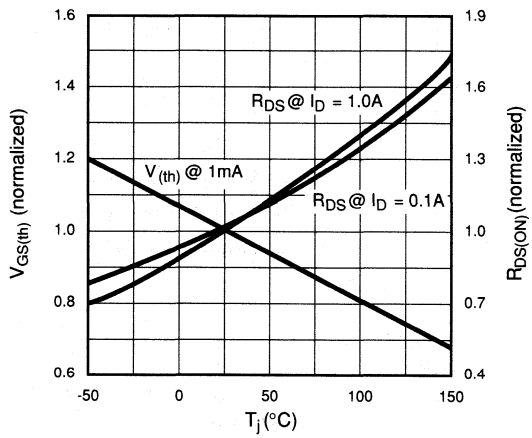
On-Resistance vs. Drain Current



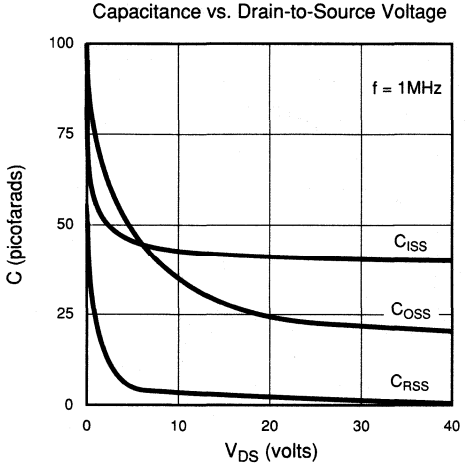
Transfer Characteristics



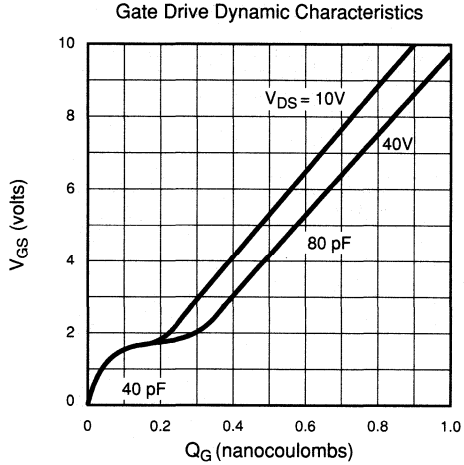
$V_{(th)}$ and R_{DS} Variation with Temperature



Capacitance vs. Drain-to-Source Voltage

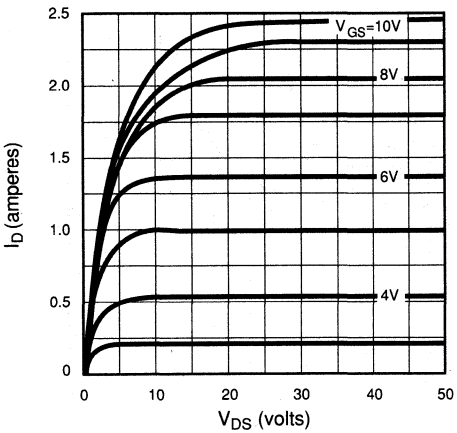


Gate Drive Dynamic Characteristics

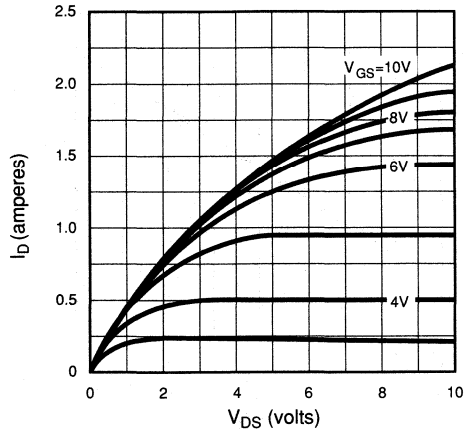


8

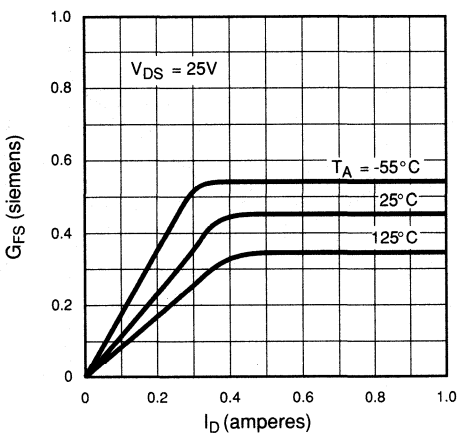
Output Characteristics



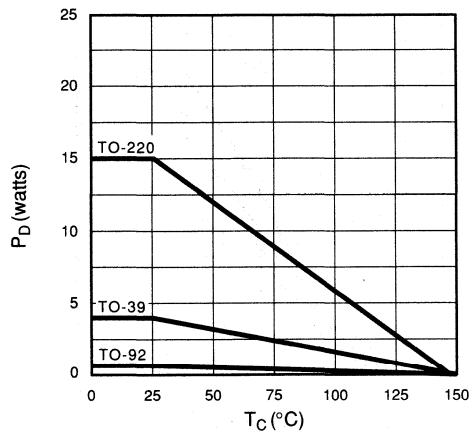
Saturation Characteristics



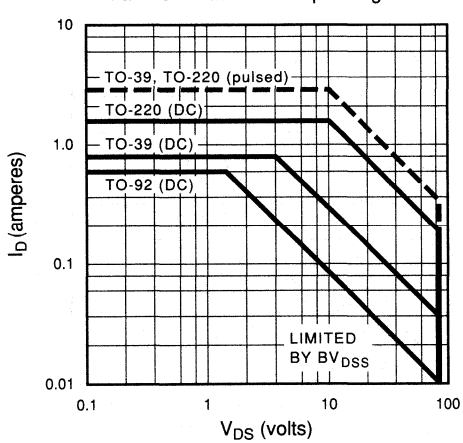
Transconductance vs. Drain Current



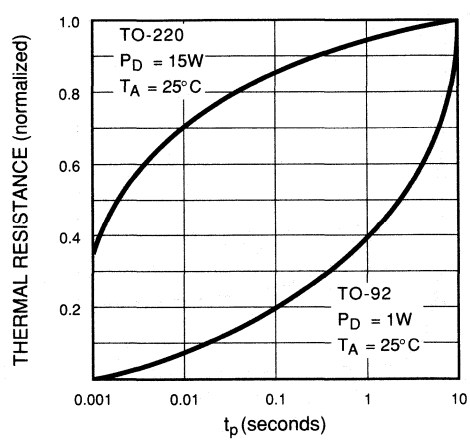
Power Dissipation vs. Case Temperature



Maximum Rated Safe Operating Area



Thermal Response Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package			
			TO-39	TO-92	TO-220	Dice†
160V	10Ω	0.4A	VN0116N2	VN0116N3	VN0116N5	VN0116ND
200V	10Ω	0.4A	VN0120N2	VN0120N3	VN0120N5	VN0120ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

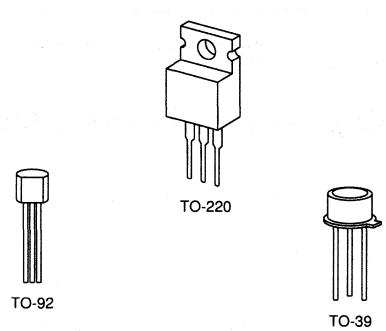
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	350mA	1.0A	3.5W	125	35	350mA	1.0A
TO-92	250mA	0.9A	1.0W	170	125	250mA	0.9A
TO-220	700mA	1.2A	15.0W	70	8.3	700mA	1.2A

* I_D (continuous) is limited by max rated T_j.

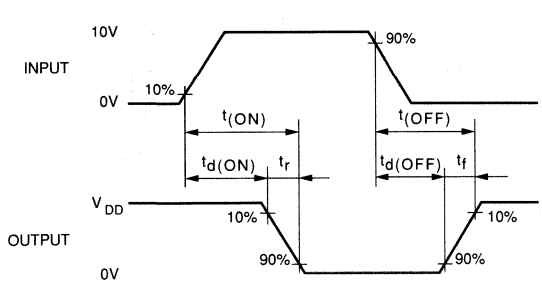
Electrical Characteristics (@ 25°C unless otherwise specified)

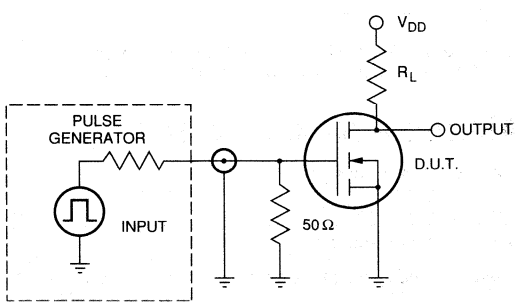
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN0120	200			V	V_{GS} = 0, I_D = 1mA
		VN0116	160				
$V_{GS(th)}$	Gate Threshold Voltage		1		3	V	V_{GS} = V_{DS}, I_D = 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-5.1	-6.0	mV/°C	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage			0.1	100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		0.3	0.6		A	V_{GS} = 5V, V_{DS} = 25V
			0.4	0.9			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			10	15	Ω	V_{GS} = 5V, I_D = 100mA
				8	10		V_{GS} = 10V, I_D = 100mA
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature			1.0	1.2	%/°C	V_{GS} = 10V, I_D = 500mA
G_{FS}	Forward Transconductance		100	160		m℧	V_{DS} = 25V, I_D = 250mA
C_{ISS}	Input Capacitance			40	55	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			20	30		
C_{RSS}	Reverse Transfer Capacitance			5	8		
$t_{d(ON)}$	Turn-ON Delay Time			3	5	ns	V_{DD} = 25V, I_D = 1A, R_S = 50Ω
t_r	Rise Time			5	8		
$t_{d(OFF)}$	Turn-OFF Delay Time			6	9		
t_f	Fall Time			5	8		
V_{SD}	Diode Forward Voltage Drop			1.2	1.8	V	V_{GS} = 0, I_{SD} = 1.0A
t_{rr}	Reverse Recovery Time			400		ns	V_{GS} = 0, I_{SD} = 1.0A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

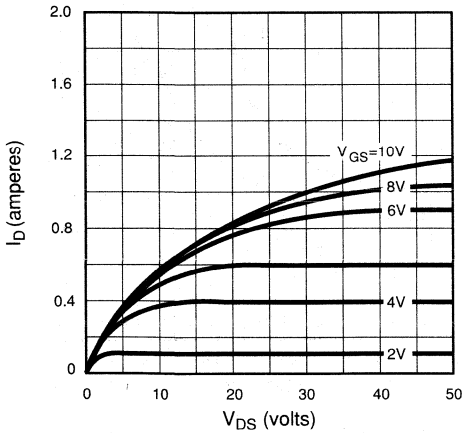
Switching Waveforms and Test Circuit



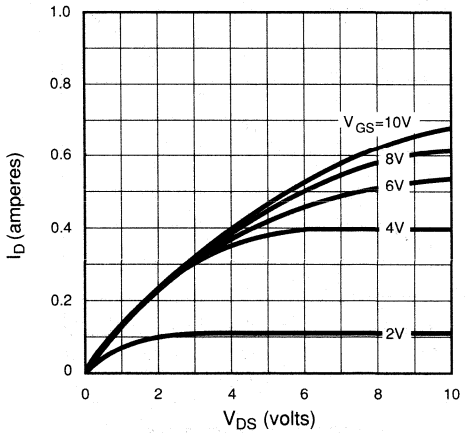


Typical Performance Curves

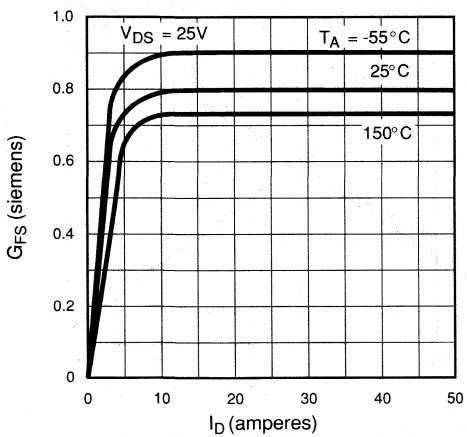
Output Characteristics



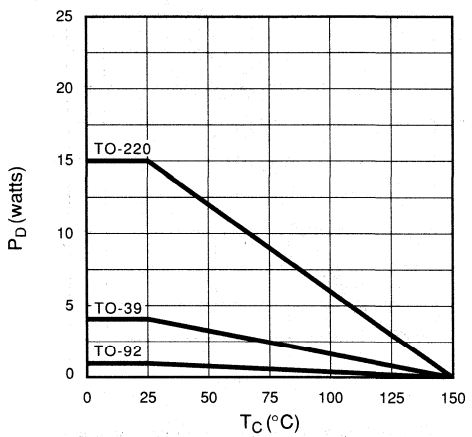
Saturation Characteristics



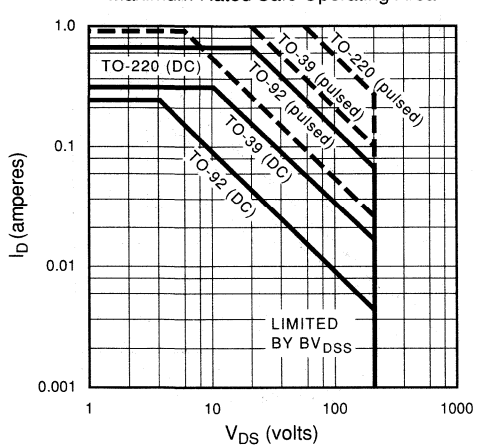
Transconductance vs. Drain Current



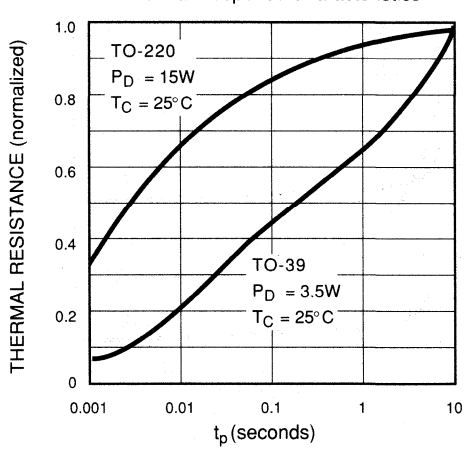
Power Dissipation vs. Case Temperature



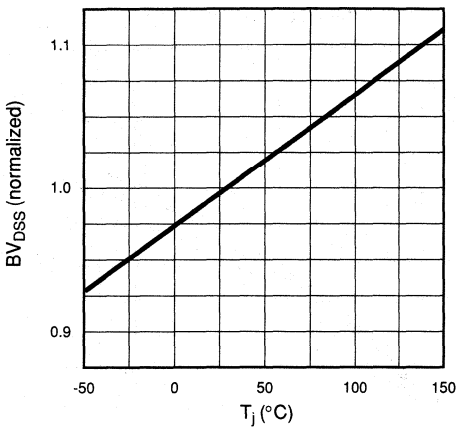
Maximum Rated Safe Operating Area



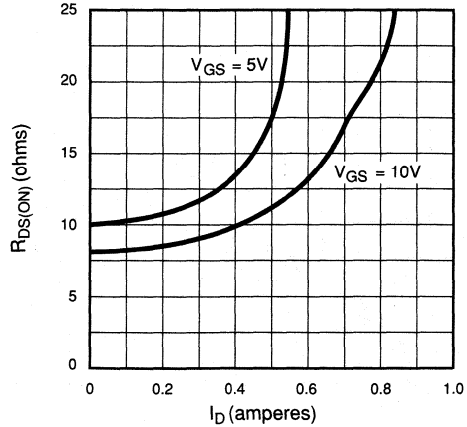
Thermal Response Characteristics



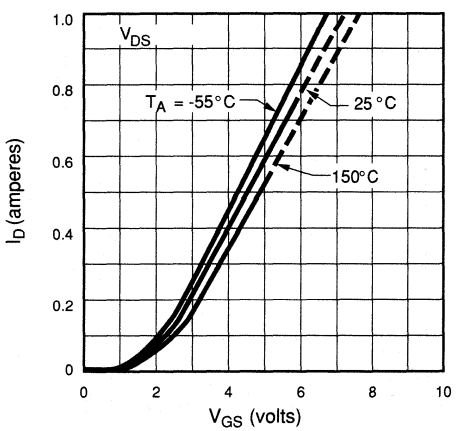
BV$_{DSS}$ Variation with Temperature



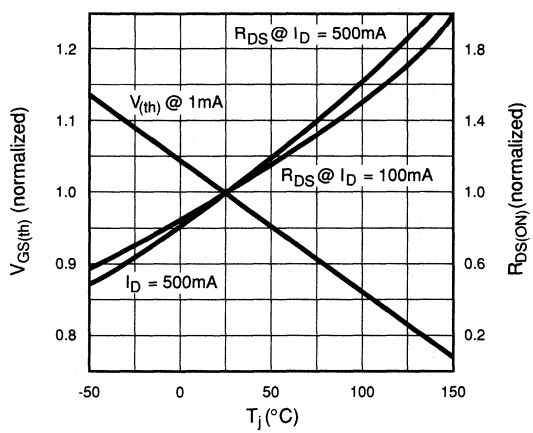
On-Resistance vs. Drain Current



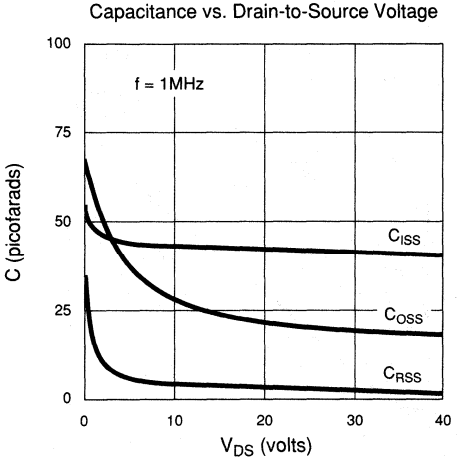
Transfer Characteristics



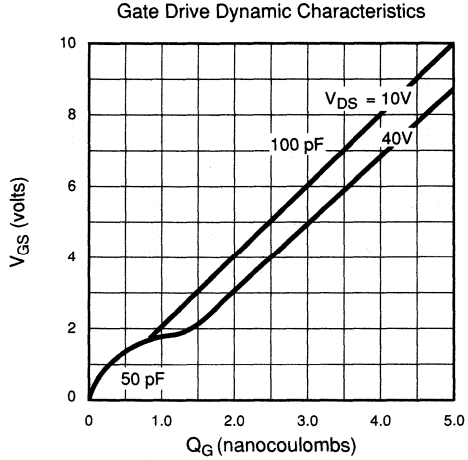
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS}/ BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package			
			TO-3	TO-39	TO-220	Dice†
350V	2.5Ω	3A	VN0335N1	VN0335N2	VN0335N5	VN0335ND
400V	2.5Ω	3A	VN0340N1	VN0340N2	VN0340N5	VN0340ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

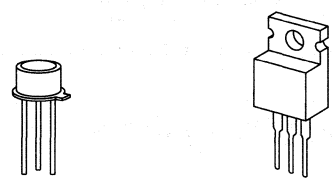
Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

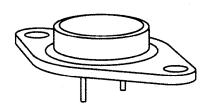
8

Package Options (Note 1)



TO-39

TO-220



TO-3

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-3	3.5A	8A	100W	30	1.25	3.5A	8.0A
TO-39	1.0A	7A	6W	125	20.8	1.0A	7.0A
TO-220	2.1A	8A	50W	40	2.5	2.1A	8.0A

* I_D (continuous) is limited by max rated T_j.

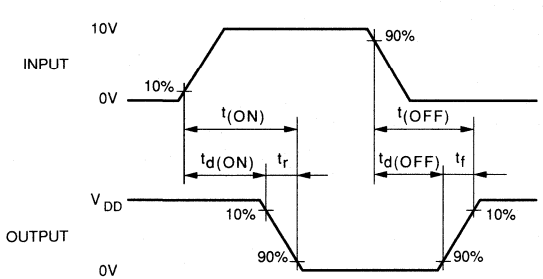
Electrical Characteristics (@ 25°C unless otherwise specified)

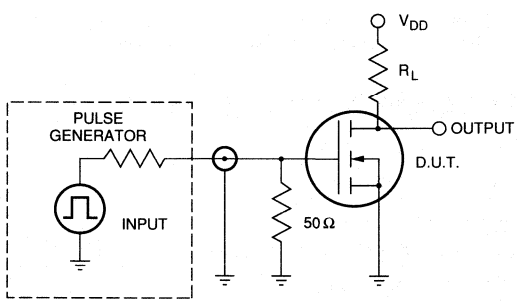
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN0340	400			V	V_{GS} = 0, I_D = 10mA
		VN0335	350				
$V_{GS(th)}$	Gate Threshold Voltage		2		4	V	V_{GS} = V_{DS}, I_D = 10mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-4.8	-6.0	mV/°C	V_{GS} = V_{DS}, I_D = 10mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				100	µA	V_{GS} = 0, V_{DS} = Max Rating
					2.0	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			4.5		A	V_{GS} = 5V, V_{DS} = 25V
			3.0	5.5			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			2.2		Ω	V_{GS} = 5V, I_D = 0.5A
				1.8	2.5		V_{GS} = 10V, I_D = 1mA
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature			1	2	%/°C	V_{GS} = 10V, I_D = 1mA
G_{FS}	Forward Transconductance		1	1.25		℧	V_{DS} = 25V, I_D = 1A
C_{ISS}	Input Capacitance			550	650	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			75	125		
C_{RSS}	Reverse Transfer Capacitance			25	50		
$t_{d(ON)}$	Turn-ON Delay Time			12	20	ns	V_{DD} = 25V, I_D = 1A, R_S = 50Ω
t_r	Rise Time			12	20		
$t_{d(OFF)}$	Turn-OFF Delay Time			65	100		
t_f	Fall Time			20	30		
V_{SD}	Diode Forward Voltage Drop			1.1	1.5	V	V_{GS} = 0, I_{SD} = 5A
t_{rr}	Reverse Recovery Time			450		ns	V_{GS} = 0, I_{SD} = 1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

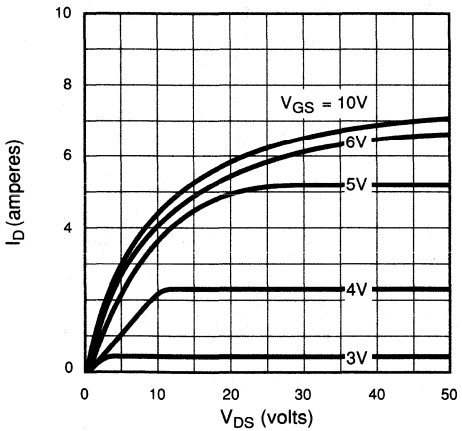
Switching Waveforms and Test Circuit



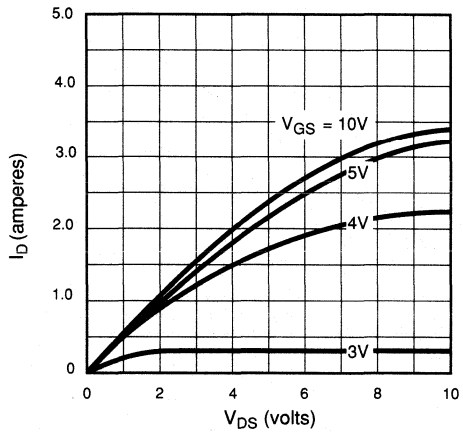


Typical Performance Curves

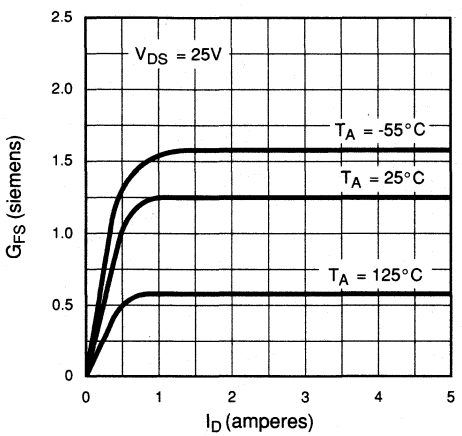
Output Characteristics



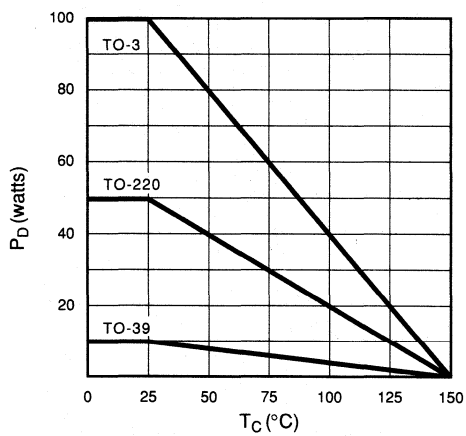
Saturation Characteristics



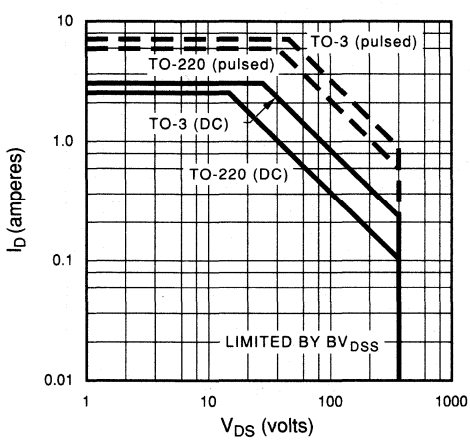
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

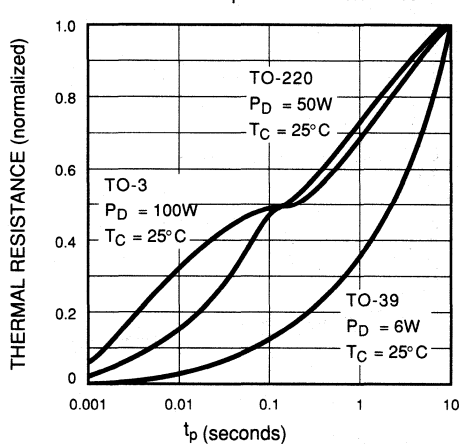


Maximum Rated Safe Operating Area



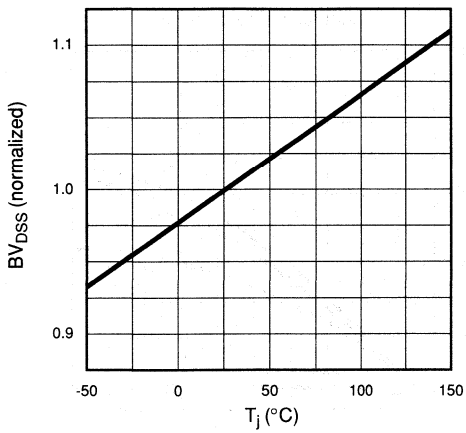
Pulsed Condition: 300μs, 2% dutycycle

Thermal Response Characteristics

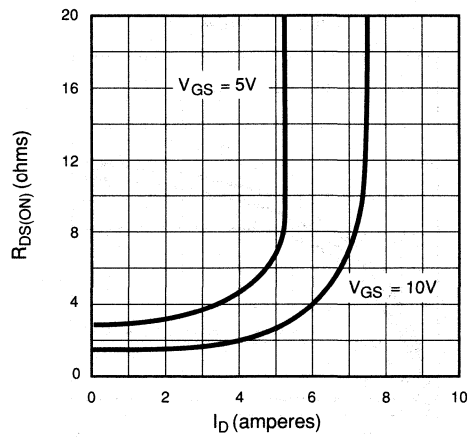


8

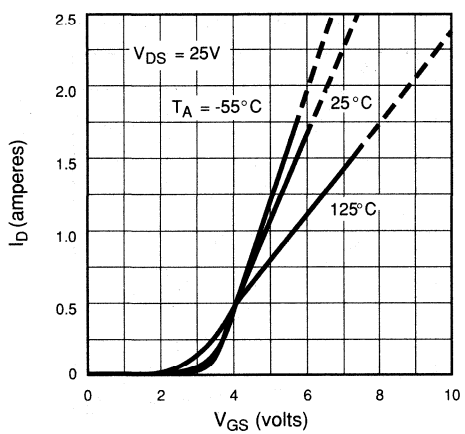
BV$_{DSS}$ Variation with Temperature



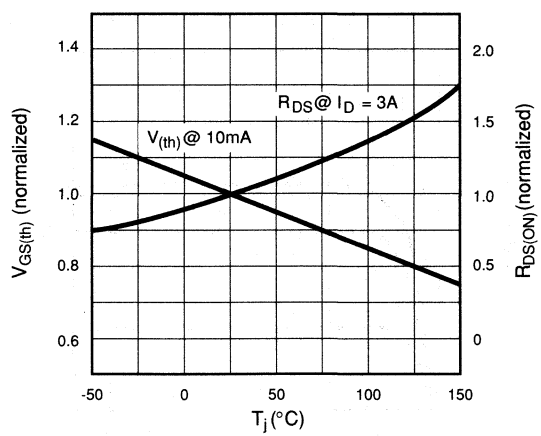
On-Resistance vs. Drain Current



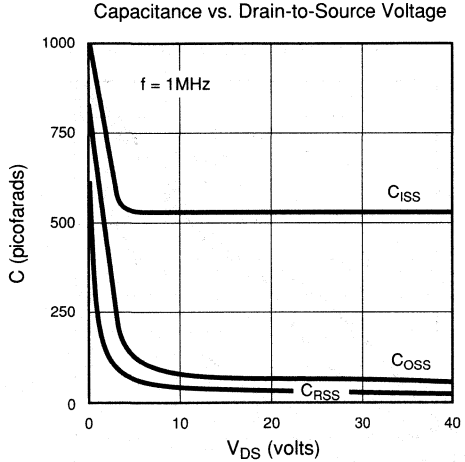
Transfer Characteristics



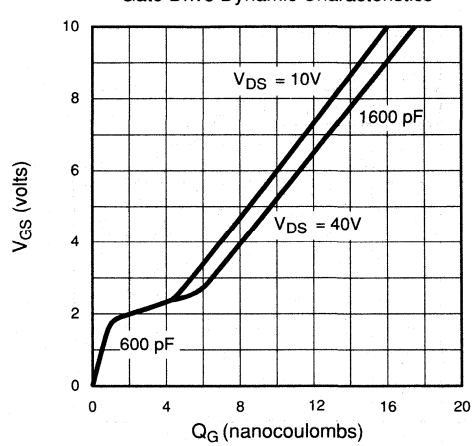
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package			
			TO-3	TO-39	TO-220	Dice†
450V	4Ω	2A	VN0345N1	VN0345N2	VN0345N5	VN0345ND
500V	4Ω	2A	VN0350N1	VN0350N2	VN0350N5	VN0350ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

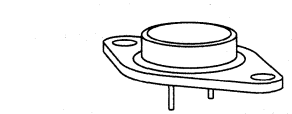
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

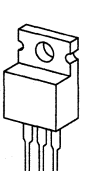
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

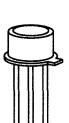
Package Options (Note 1)



TO-3



TO-220



TO-39

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-3	2.5A	5.0A	100W	30	1.25	2.5A	5.0A
TO-39	0.35A	4.5A	6W	125	20.8	0.35A	4.5A
TO-220	1.5A	5.0A	50W	40	2.5	1.5A	5.0A

* I_D (continuous) is limited by max rated T_j.

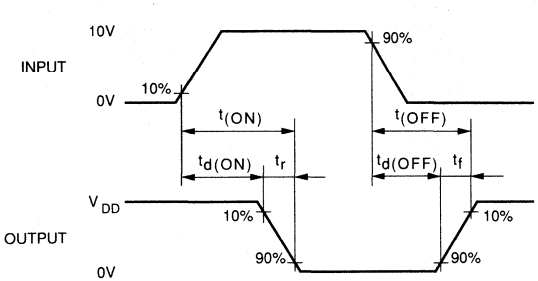
Electrical Characteristics (@ 25°C unless otherwise specified)

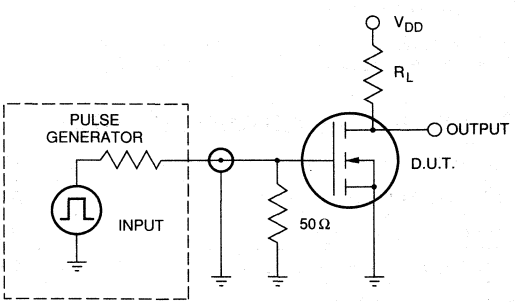
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN0350	500			V	V_{GS} = 0, I_D = 10mA
		VN0345	450				
$V_{GS(th)}$	Gate Threshold Voltage		2		4	V	V_{GS} = V_{DS}, I_D = 10mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-7.0	-9.0	mV/°C	V_{GS} = V_{DS}, I_D = 10mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				100	µA	V_{GS} = 0, V_{DS} = Max Rating
					2.0	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			2.6		A	V_{GS} = 5V, V_{DS} = 25V
			2.0	6.0			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			3.5		Ω	V_{GS} = 5V, I_D = 0.5A
				2.8	4.0		V_{GS} = 10V, I_D = 0.5A
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature			1	1.5	%/°C	V_{GS} = 10V, I_D = 0.5A
G_{FS}	Forward Transconductance		500	1000		m℧	V_{DS} = 25V, I_D = 0.5A
C_{ISS}	Input Capacitance			550	650	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			90	125		
C_{RSS}	Reverse Transfer Capacitance			15	50		
$t_{d(ON)}$	Turn-ON Delay Time			8	15	ns	V_{DD} = 25V, I_D = 1A, R_S = 50Ω
t_r	Rise Time			8	15		
$t_{d(OFF)}$	Turn-OFF Delay Time			65	100		
t_f	Fall Time			15	25		
V_{SD}	Diode Forward Voltage Drop			1.3	1.8	V	V_{GS} = 0, I_{SD} = 1.0A
t_{rr}	Reverse Recovery Time			450		ns	V_{GS} = 0, I_{SD} = 0.5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

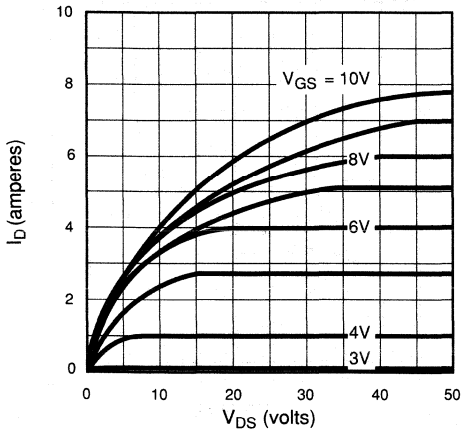
Switching Waveforms and Test Circuit



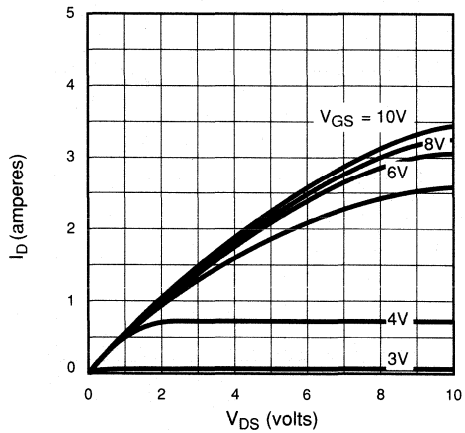


Typical Performance Curves

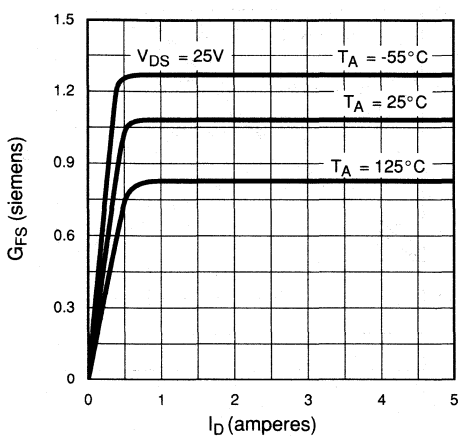
Output Characteristics



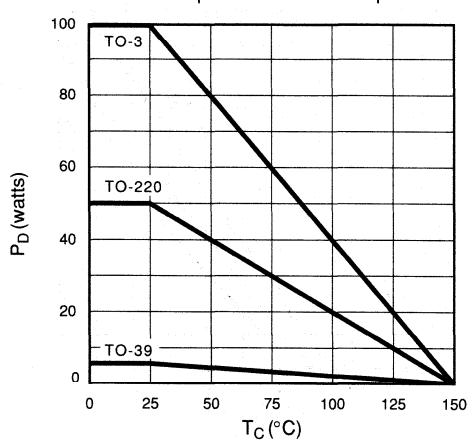
Saturation Characteristics



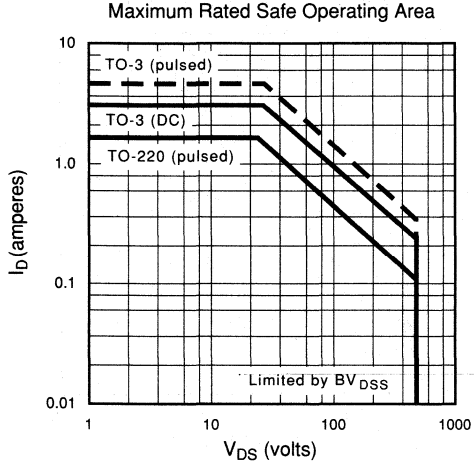
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

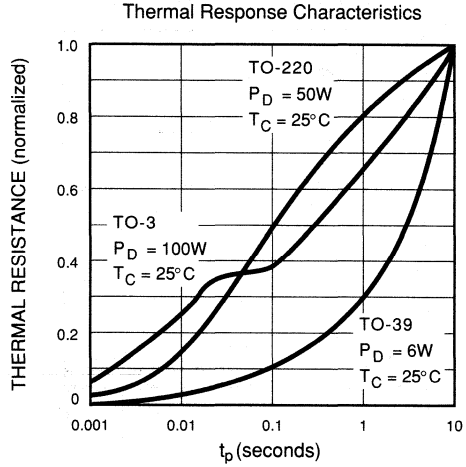


Maximum Rated Safe Operating Area



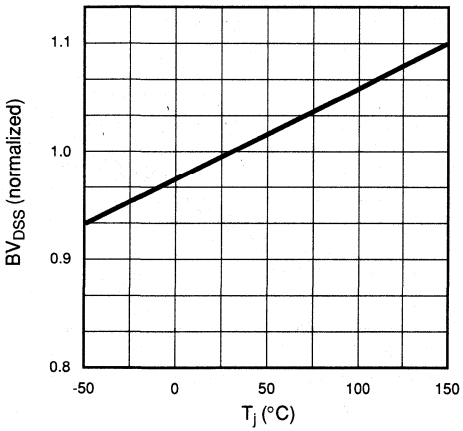
Pulsed Condition: 300µs, 2% dutycycle

Thermal Response Characteristics

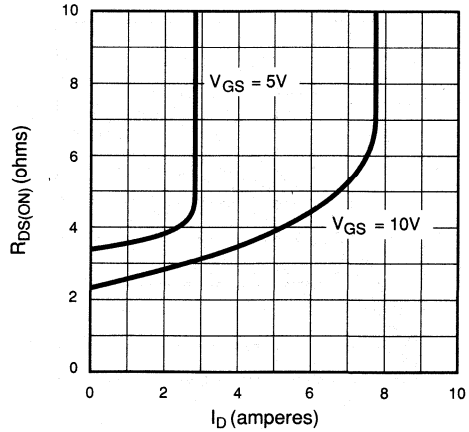


8

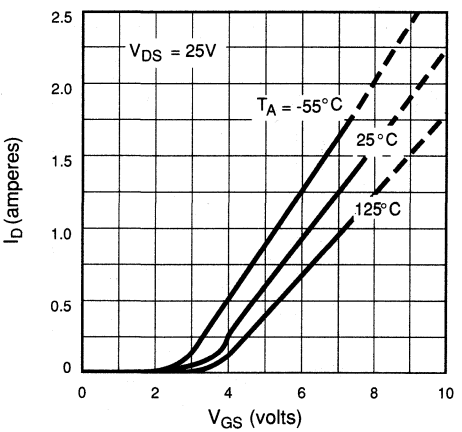
BV$_{DSS}$ Variation with Temperature



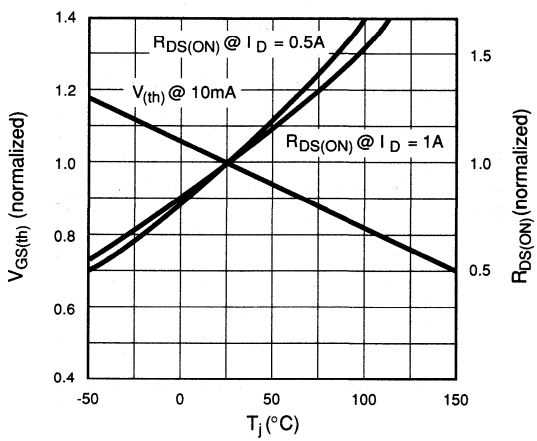
On-Resistance vs. Drain Current



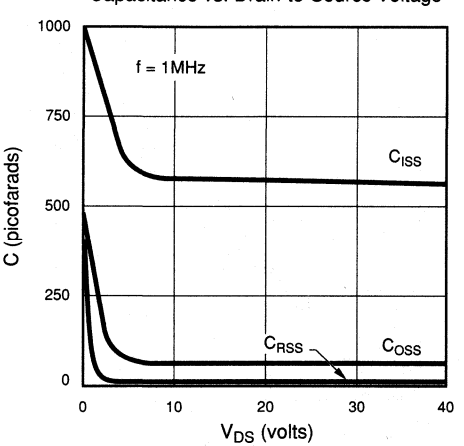
Transfer Characteristics



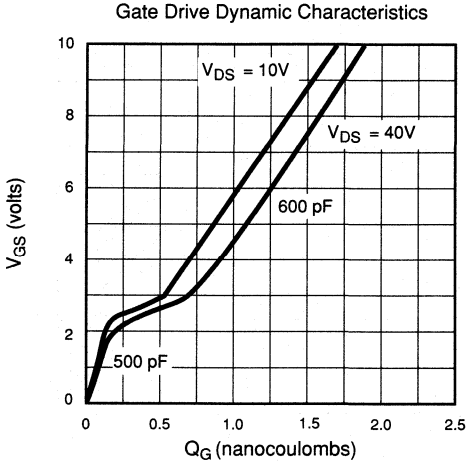
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-3	TO-220	Dice†
550V	6Ω	1.5A	VN0355N1	VN0355N5	VN0355ND
600V	6Ω	1.5A	VN0360N1	VN0360N5	VN0360ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)
- ☐ Amplifiers
- ☐ Switches

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

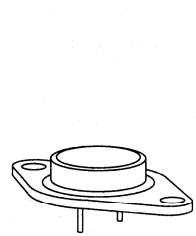
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

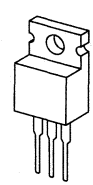
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-3



TO-220

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-3	2.5A	6A	100W	30	1.25	2.5A	6.0A
TO-220	1.5A	6A	50W	2.5	2.5	1.5A	6.0A

* I_D (continuous) is limited by max rated T_j.

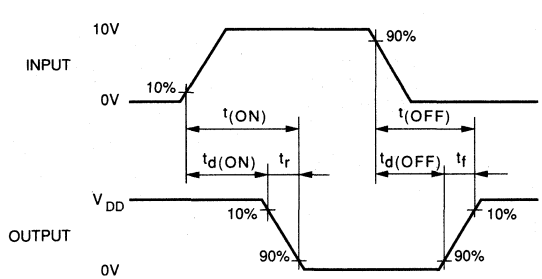
Electrical Characteristics (@ 25°C unless otherwise specified)

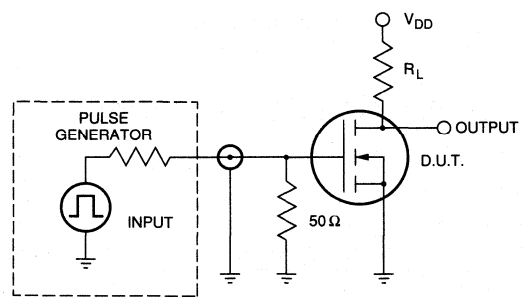
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN0360	600			V	V_{GS} = 0, I_D = 10mA
		VN0355	550				
$V_{GS(th)}$	Gate Threshold Voltage		2		4	V	V_{GS} = V_{DS}, I_D = 10mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-4.8	-6.0	mV/°C	V_{GS} = V_{DS}, I_D = 10mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				100	µA	V_{GS} = 0, V_{DS} = Max Rating
					2.0	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			2.1		A	V_{GS} = 5V, V_{DS} = 25V
			1.5	3.2			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			5.5		Ω	V_{GS} = 5V, I_D = 0.5A
				4.5	6.0		V_{GS} = 10V, I_D = 0.5A
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature			1	2	%/°C	V_{GS} = 10V, I_D = 0.5A
G_{FS}	Forward Transconductance		0.5	1		℧	V_{DS} = 25V, I_D = 0.5A
C_{ISS}	Input Capacitance			550	650	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			75	125		
C_{RSS}	Reverse Transfer Capacitance			25	50		
$t_{d(ON)}$	Turn-ON Delay Time			8	15	ns	V_{DD} = 25V, I_D = 0.5A, R_S = 50Ω
t_r	Rise Time			8	15		
$t_{d(OFF)}$	Turn-OFF Delay Time			65	100		
t_f	Fall Time			12	25		
V_{SD}	Diode Forward Voltage Drop			1.1	1.5	V	V_{GS} = 0, I_{SD} = 5A
t_{rr}	Reverse Recovery Time			450		ns	V_{GS} = 0, I_{SD} = 5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

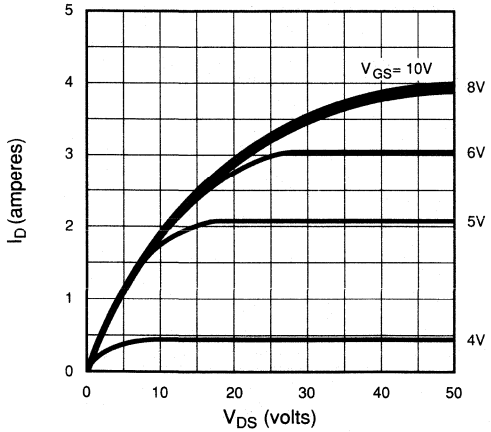
Switching Waveforms and Test Circuit



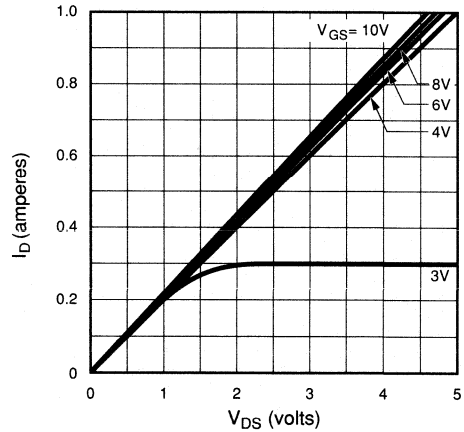


Typical Performance Curves

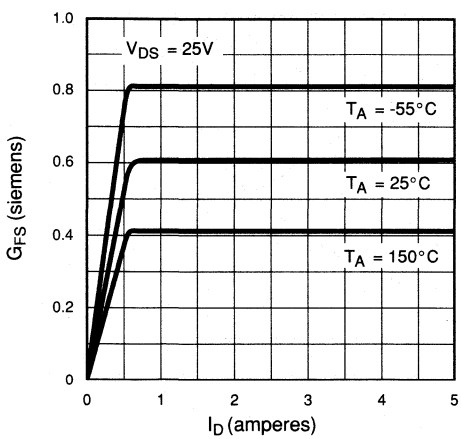
Output Characteristics



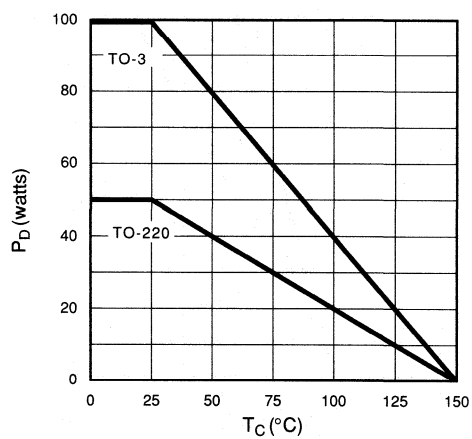
Saturation Characteristics



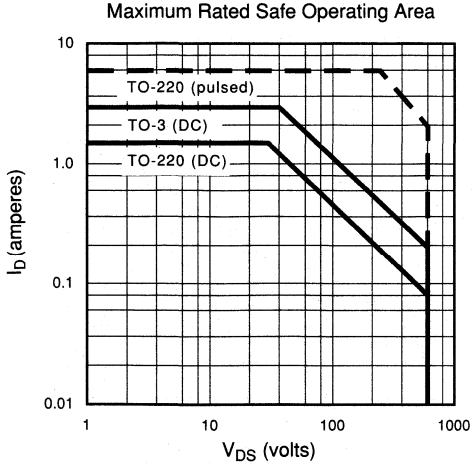
Transconductance vs. Drain Current



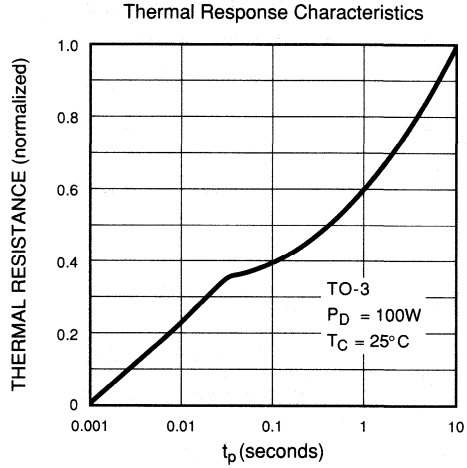
Power Dissipation vs. Case Temperature



Maximum Rated Safe Operating Area

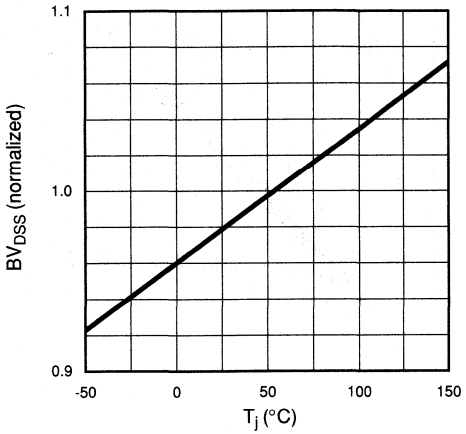


Thermal Response Characteristics

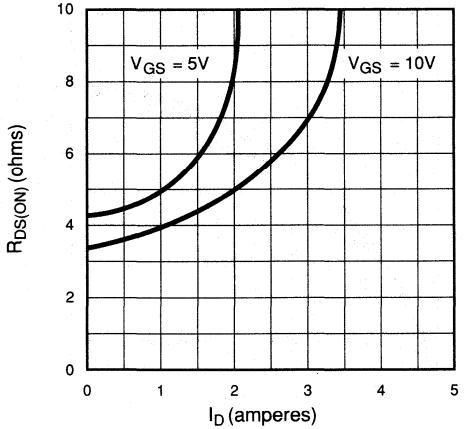


8

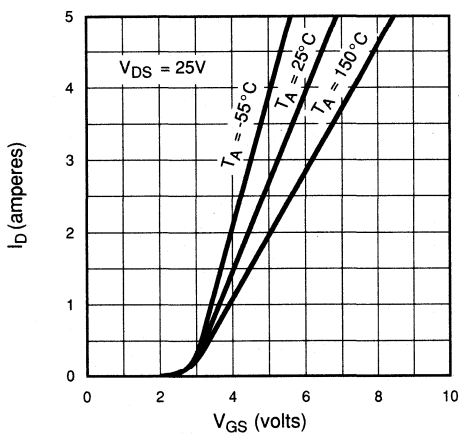
BV$_{DSS}$ Variation with Temperature



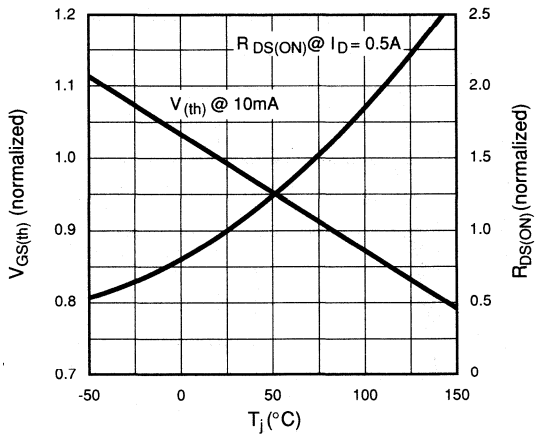
On-Resistance vs. Drain Current



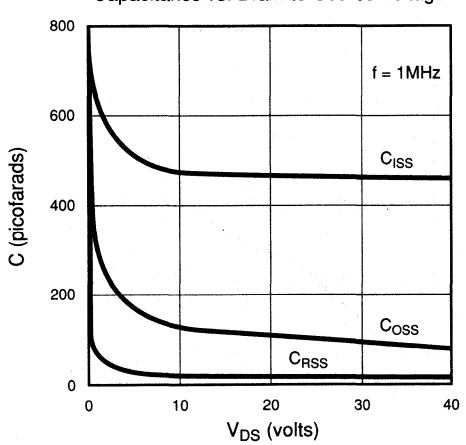
Transfer Characteristics



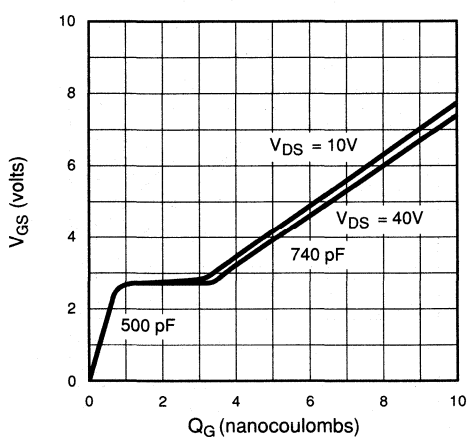
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
			TO-39	TO-92
30V	1.2Ω	2.0A	VN0300B	VN0300L

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

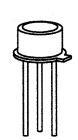
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

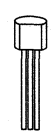
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-39



TO-92

Note 1:See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W
TO-39	1.2A	3A	6.25W	170	20
TO-92	0.4A	3A	4W	312.5	40

* I_D (continuous) is limited by max rated T_j.

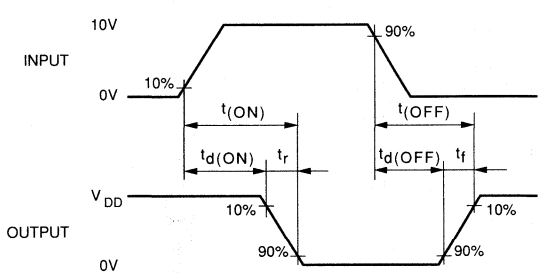
Electrical Characteristics (@ 25°C unless otherwise specified)

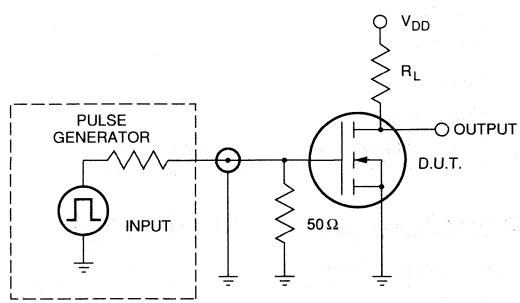
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	30			V	V_{GS} = 0, I_D =10μA
$V_{GS(th)}$	Gate Threshold Voltage	0.8		2.5	V	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage			100	nA	V_{GS} = ±30V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			10	μA	V_{GS} = 0, V_{DS} = Max Rating
				500		V_{GS} = 0, V_{DS} = 50V T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	2			A	V_{GS} = 0.1V, V_{DS} ≥ $2V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resostance			3.3	Ω	V_{GS} = 5V, I_D = 0.3A
				1.2		V_{GS} = 10V, I_D = 1A
G_{FS}	Forward Transconductance	200			m℧	V_{DS} ≥ $2V_{DS(ON)}$, I_D = 0.5A
C_{ISS}	Input Capacitance			150	pF	V_{GS} = 0V, V_{DS} = 15V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			95		
C_{RSS}	Reverse Transfer Capacitance			25		
$td_{(ON)}$	Turn-ON Delay Time			30	ns	V_{DD} = 25V, I_D = 1.0A R_S = 50Ω
$td_{(OFF)}$	Turn-OFF Delay Time			30		
V_{SD}	Diode Forward Voltage Drop		0.9		V	I_{SD} = 0.63A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300μs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-92	Dice†
350V	35Ω	250mA	VN0535N2	VN0535N3	VN0535ND
400V	35Ω	250mA	VN0540N2	VN0540N3	VN0540ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

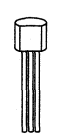
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

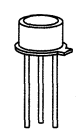
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92



TO-39

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	250mA	500mA	6.0W	125	20.8	250mA	500mA
TO-92	100mA	400mA	1.0W	170	125	100mA	400mA

* I_D (continuous) is limited by max rated T_j.

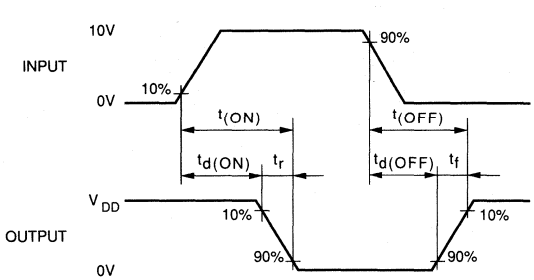
Electrical Characteristics (@ 25°C unless otherwise specified)

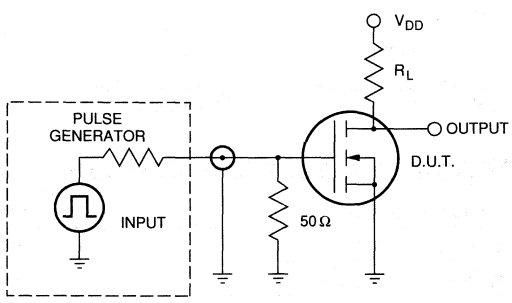
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN0540	400			V	V_{GS} = 0, I_D = 1mA
		VN0535	350				
$V_{GS(th)}$	Gate Threshold Voltage		2		4	V	V_{GS} = V_{DS}, I_D = 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.5	-4.5	mV/°C	
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					500		V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			300		mA	V_{GS} = 5V, V_{DS} = 25V
			250	340			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			30		Ω	V_{GS} = 5V, I_D = 20mA
				25	35		V_{GS} = 10V, I_D = 0.1A
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature			0.9	1.5	%/°C	V_{GS} = 10V, I_D = 0.1A
G_{FS}	Forward Transconductance		100	180		m℧	V_{DS} = 25V, I_D = 0.1A
C_{ISS}	Input Capacitance			45	55	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			8	10		
C_{RSS}	Reverse Transfer Capacitance			2	5		
$t_{d(ON)}$	Turn-ON Delay Time			3	5	ns	V_{DD} = 25V, I_D = 50mA, R_S = 50Ω
t_r	Rise Time			3	5		
$t_{d(OFF)}$	Turn-OFF Delay Time			3	5		
t_f	Fall Time			3	5		
V_{SD}	Diode Forward Voltage Drop			0.8		V	V_{GS} = 0, I_{SD} = 0.5A
t_{rr}	Reverse Recovery Time			400		ns	V_{GS} = 0, I_{SD} = 0.5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

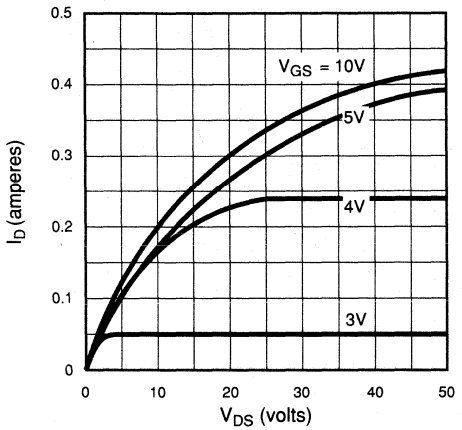
Switching Waveforms and Test Circuit



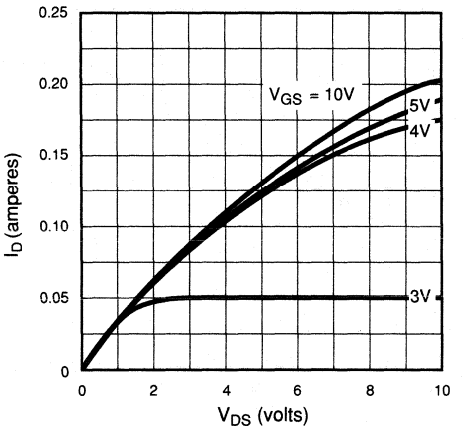


Typical Performance Curves

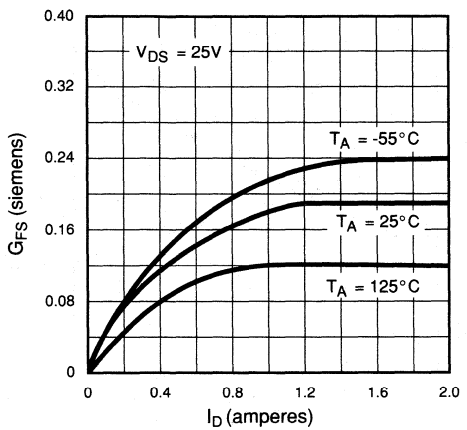
Output Characteristics



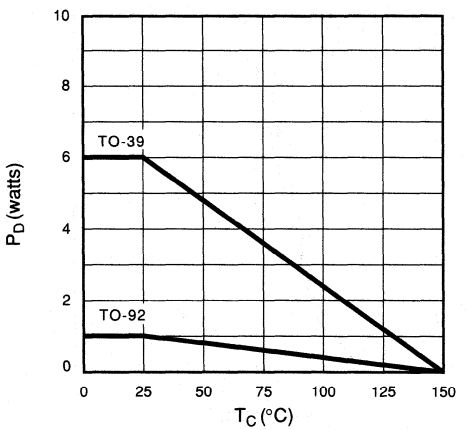
Saturation Characteristics



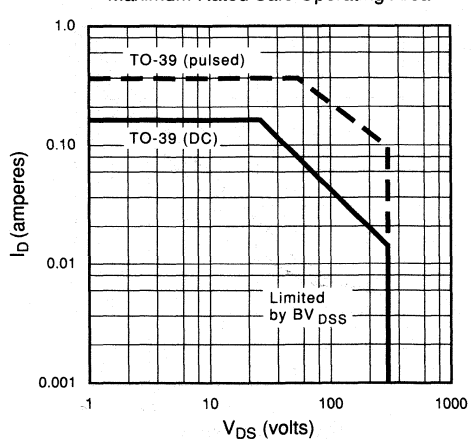
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

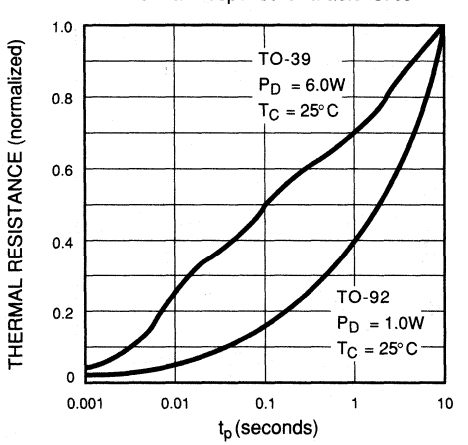


Maximum Rated Safe Operating Area



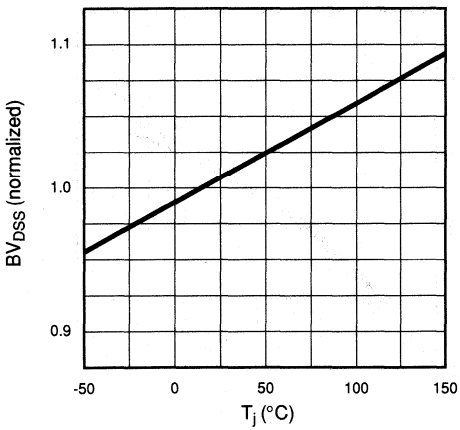
Pulsed Condition: 300μs, 2% dutycycle

Thermal Response Characteristics

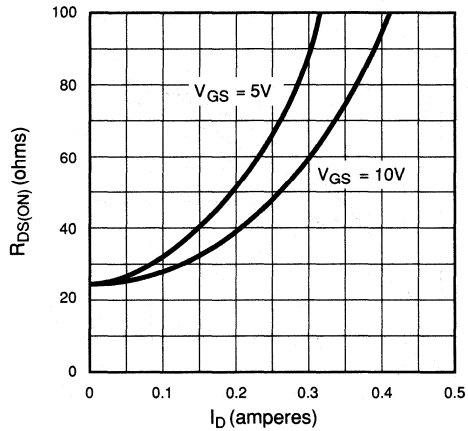


8

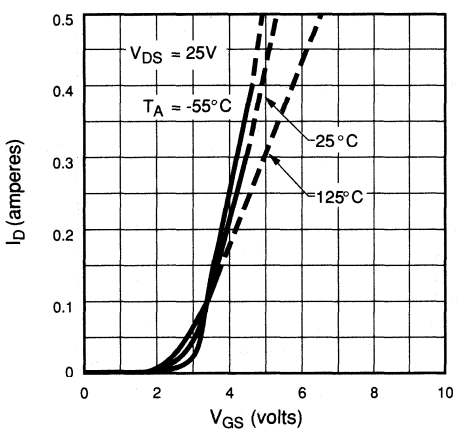
BV_{DSS} Variation with Temperature



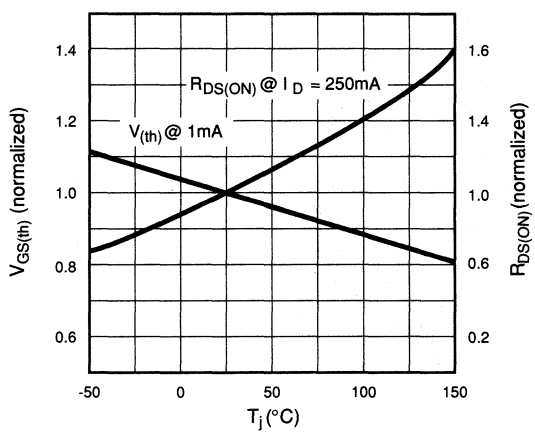
On-Resistance vs. Drain Current



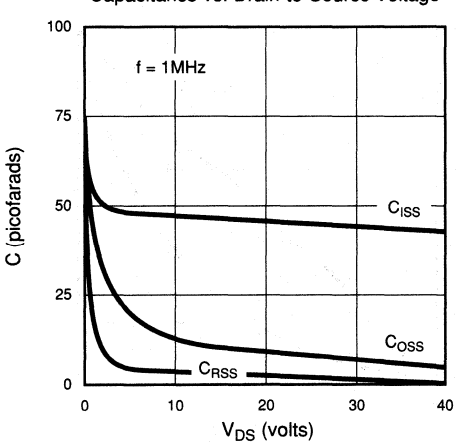
Transfer Characteristics



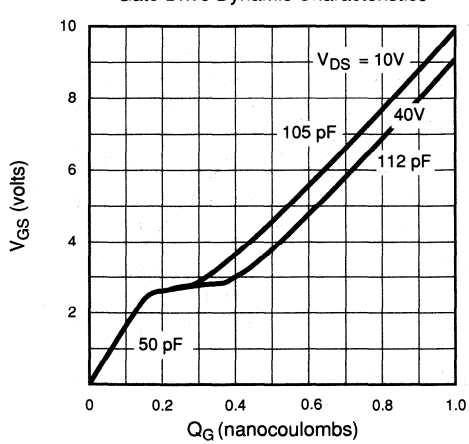
$V_{(th)}$ and R_{DS} Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-92	Dice†
450V	60Ω	150mA	VN0545N2	VN0545N3	VN0545ND
500V	60Ω	150mA	VN0550N2	VN0550N3	VN0550ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

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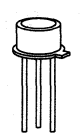
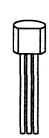
8

Package Options (Note 1)



TO-39



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	100mA	300mA	6.0W	125	20	100mA	300mA
TO-92	50mA	250mA	1.0W	170	125	50mA	250mA

* I_D (continuous) is limited by max rated T_j.

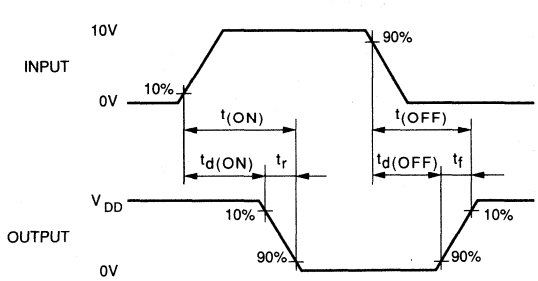
Electrical Characteristics (@ 25°C unless otherwise specified)

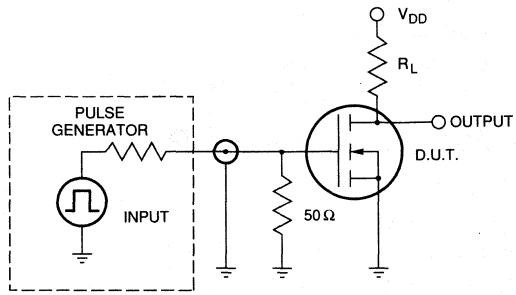
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN0550	500			V	V_{GS} = 0, I_D = 1mA
		VN0545	450				
$V_{GS(th)}$	Gate Threshold Voltage		2		4	V	V_{GS} = V_{DS}, I_D = 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.8	-5.0	mV/°C	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					1000		V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			100		mA	V_{GS} = 5V, V_{DS} = 25V
			150	200			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			50		Ω	V_{GS} = 5V, I_D = 50mA
				45	60		V_{GS} = 10V, I_D = 50mA
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature			1	1.7	%/°C	V_{GS} = 10V, I_D = 50mA
G_{FS}	Forward Transconductance		50	75		m℧	V_{DS} = 25V, I_D = 50mA
C_{ISS}	Input Capacitance			45	55	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			8	10		
C_{RSS}	Reverse Transfer Capacitance			2	5		
$t_{d(ON)}$	Turn-ON Delay Time			3	5	ns	V_{DD} = 25V, I_D = 50mA, R_S = 50Ω
t_r	Rise Time			3	5		
$t_{d(OFF)}$	Turn-OFF Delay Time			3	5		
t_f	Fall Time			3	5		
V_{SD}	Diode Forward Voltage Drop			0.8		V	V_{GS} = 0, I_{SD} = 0.5A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 0.5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

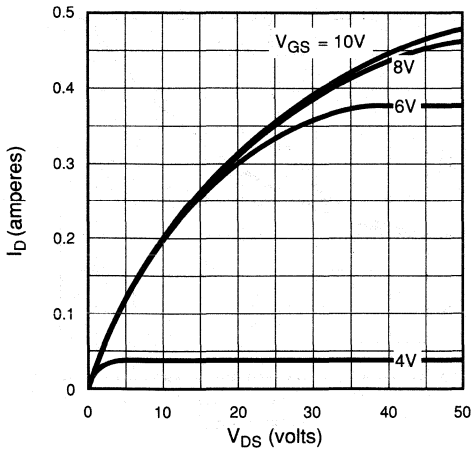
Switching Waveforms and Test Circuit



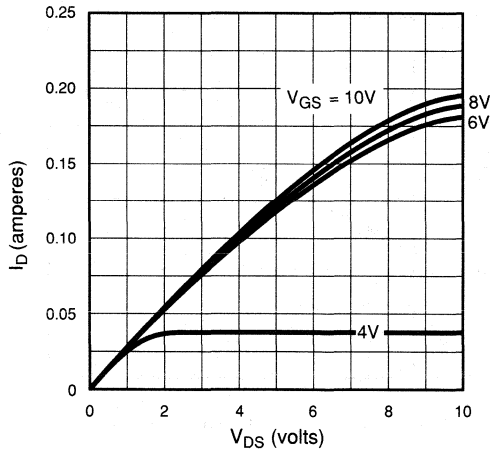


Typical Performance Curves

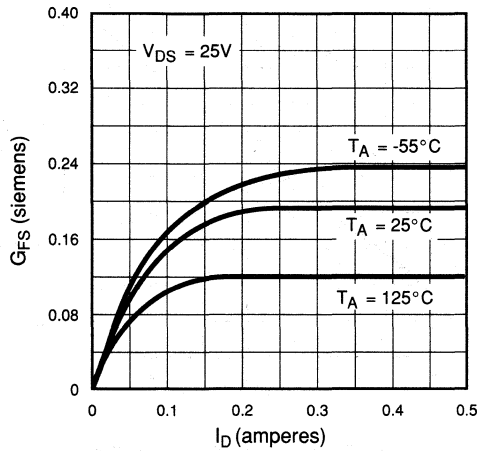
Output Characteristics



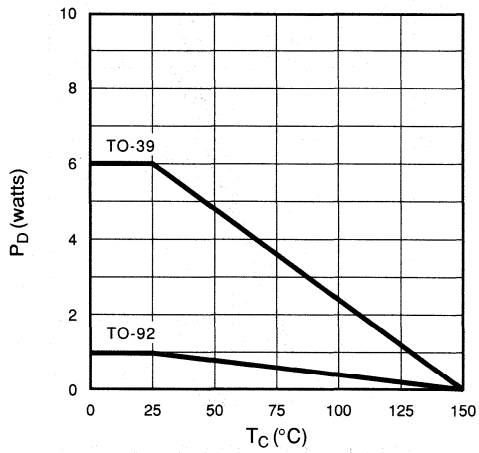
Saturation Characteristics



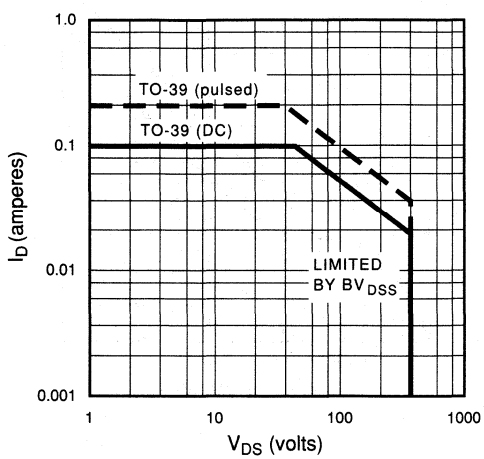
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

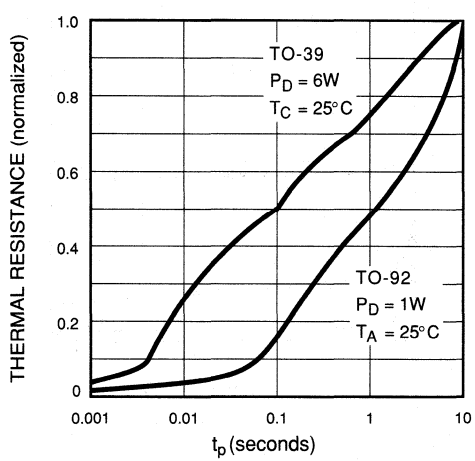


Maximum Rated Safe Operating Area



Pulsed Condition: 300µs, 2% dutycycle

Thermal Response Characteristics



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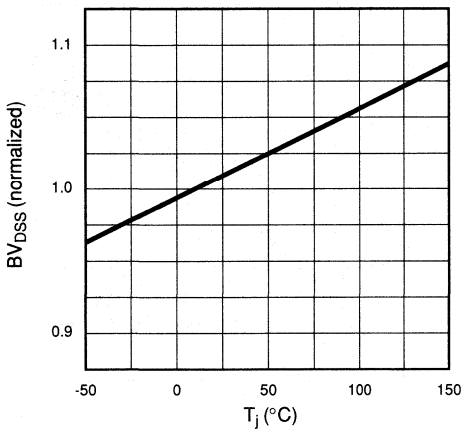
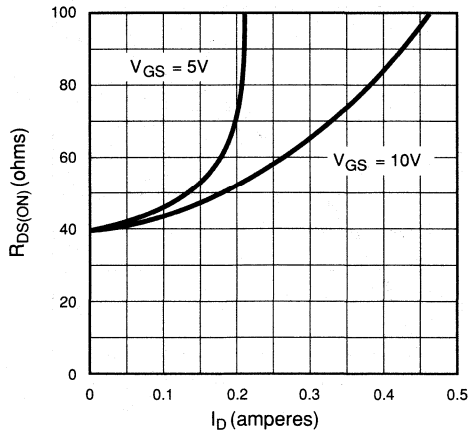
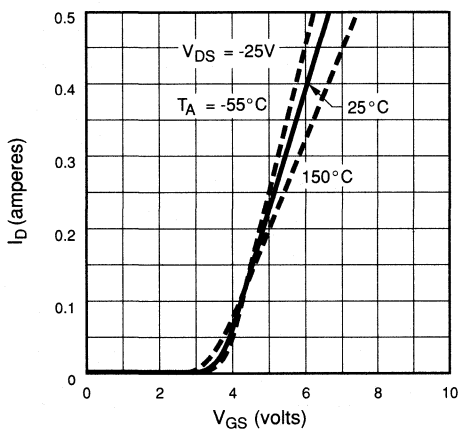
BV$_{DSS}$ Variation with Temperature



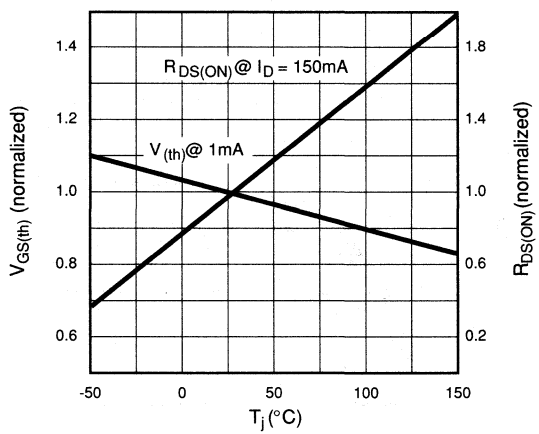
On-Resistance vs. Drain Current



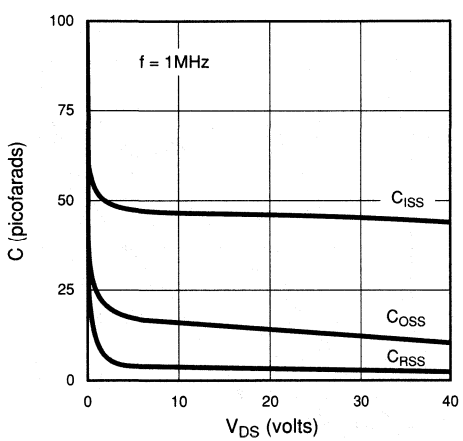
Transfer Characteristics



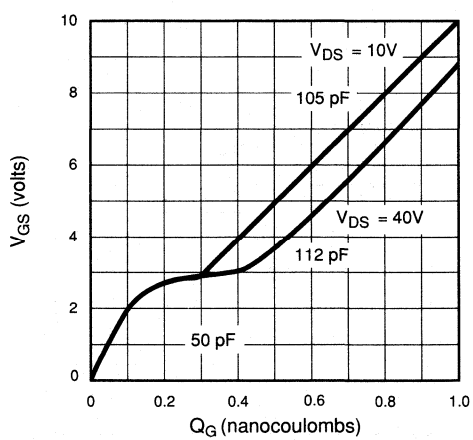
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package			
			TO-39	TO-92	TO-220	Dice†
350V	10Ω	0.75A	VN0635N2	VN0635N3	VN0635N5	VN0635ND
400V	10Ω	0.75A	VN0640N2	VN0640N3	VN0640N5	VN0640ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

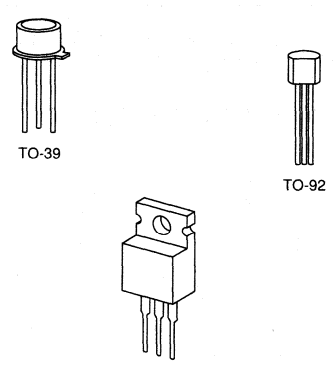
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	0.6A	2.5A	6W	21	125	0.6A	2.5A
TO-92	0.25A	1.5A	1W	125	170	0.25A	1.5A
TO-220	1.6A	2.5A	45W	2.7	70	1.6A	2.5A

* I_D (continuous) is limited by max rated T_j.

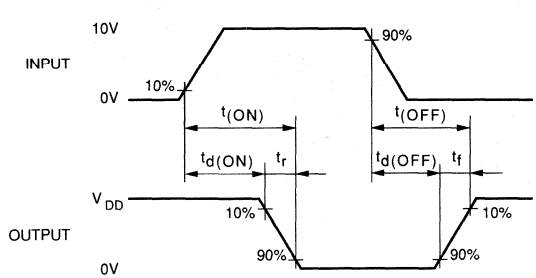
Electrical Characteristics (@ 25°C unless otherwise specified)

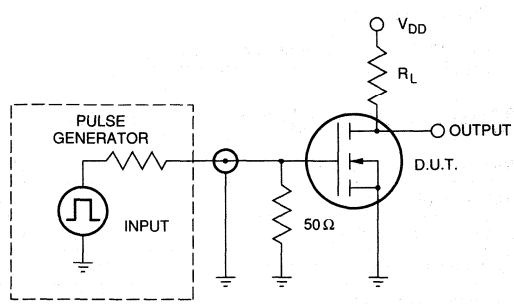
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN0635	350			V	V_{GS} = 0, I_D = 2mA
		VN0640	400				
$V_{GS(th)}$	Gate Threshold Voltage		2		4	V	V_{GS} = V_{DS}, I_D = 2mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				-4.0	mV/°C	V_{GS} = V_{DS}, I_D = 2mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			0.6		A	V_{GS} = 5V, V_{DS} = 25V
			0.75				V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			8		Ω	V_{GS} = 5V, I_D = 100mA
				8	10		V_{GS} = 10V, I_D = 500mA
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature				0.75	%/°C	V_{GS} = 10V, I_D = 500mA
G_{FS}	Forward Transconductance		0.1			℧	V_{DS} = 25V, I_D = 500mA
C_{ISS}	Input Capacitance			105	130	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			25	75		
C_{RSS}	Reverse Transfer Capacitance			10	20		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = 25V, I_D = 0.5A, R_S = 50Ω
t_r	Rise Time				10		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				10		
V_{SD}	Diode Forward Voltage Drop				1.8	V	V_{GS} = 0, I_{SD} = 0.5A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 0.5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

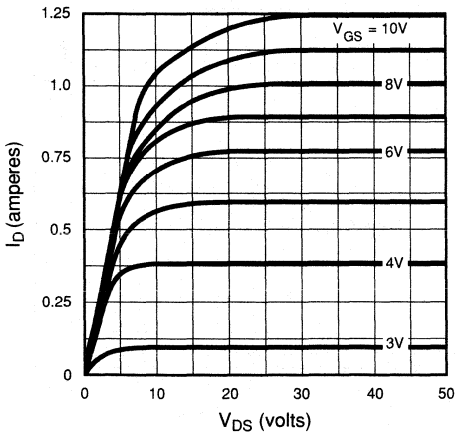
Switching Waveforms and Test Circuit



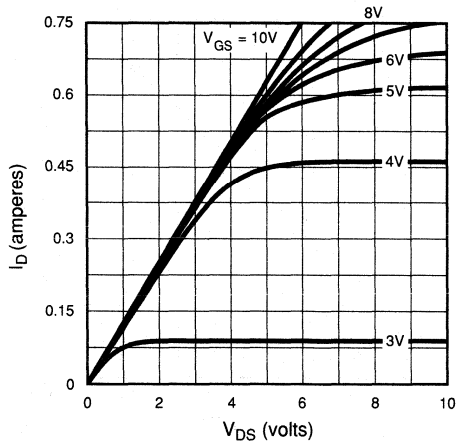


Typical Performance Curves

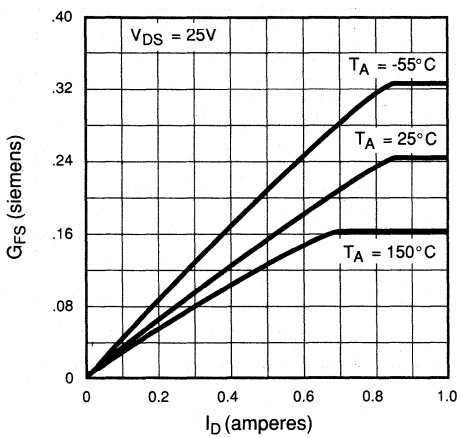
Output Characteristics



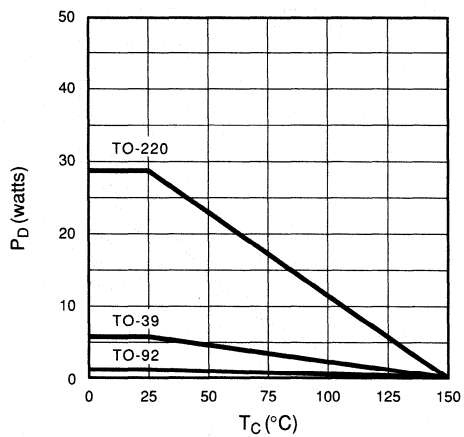
Saturation Characteristics



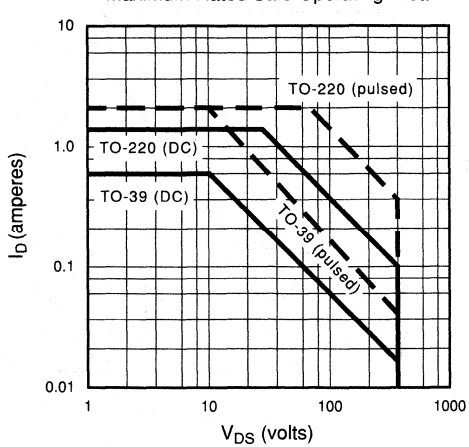
Transconductance vs. Drain Current



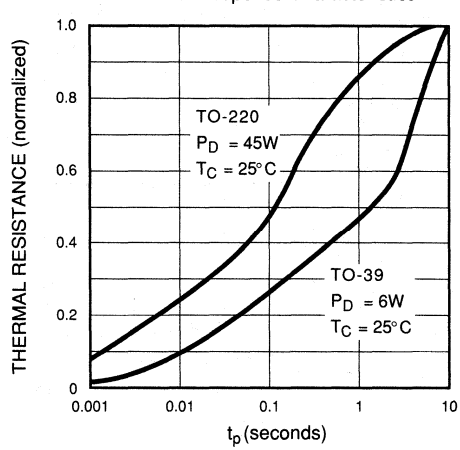
Power Dissipation vs. Case Temperature



Maximum Rated Safe Operating Area

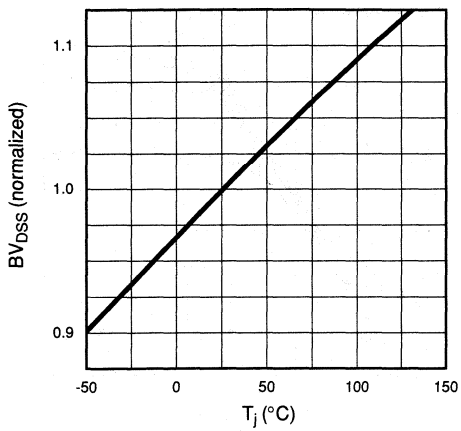


Thermal Response Characteristics

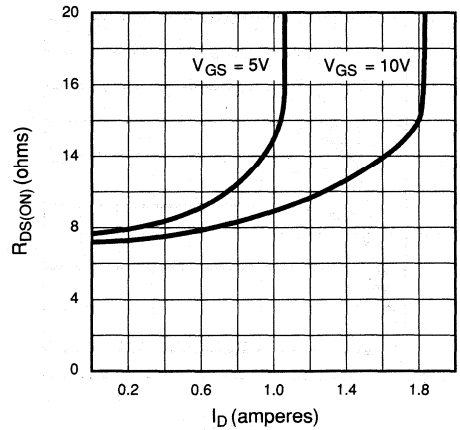


8

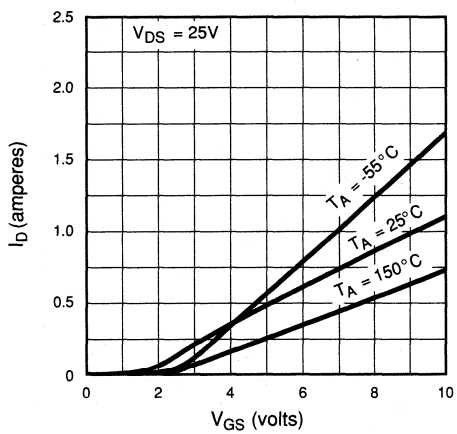
BV$_{DSS}$ Variation with Temperature



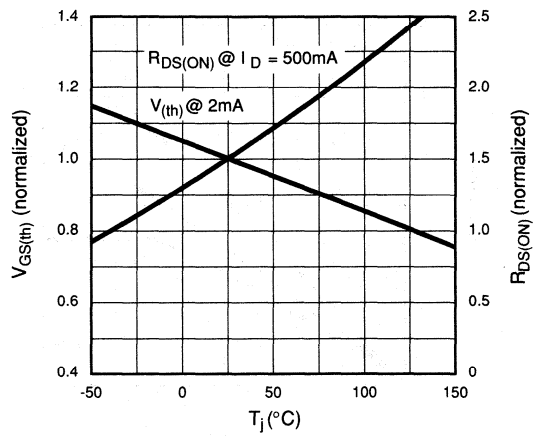
On-Resistance vs. Drain Current



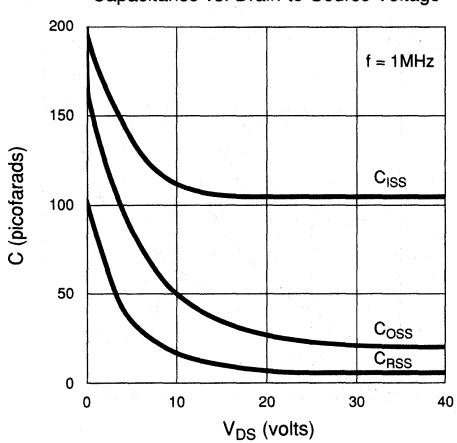
Transfer Characteristics



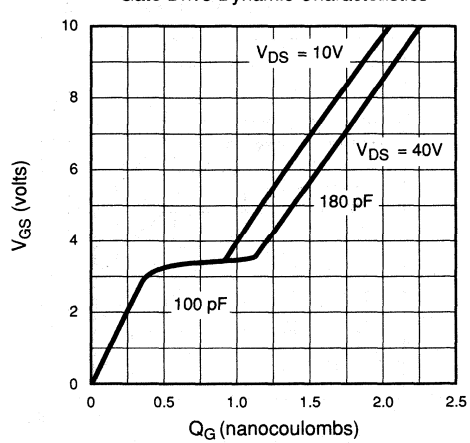
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package			
			TO-39	TO-92	TO-220	Dice†
450V	16Ω	0.5A	VN0645N2	VN0645N3	VN0645N5	VN0645ND
500V	16Ω	0.5A	VN0650N2	VN0650N3	VN0650N5	VN0650ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

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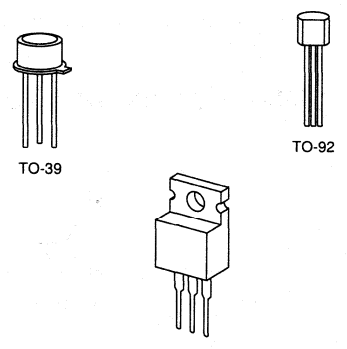
Package Options (Note 1)



Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	0.4A	1.5A	6W	125	21	0.4A	1.5A
TO-92	0.2A	1.0A	1W	170	125	0.2A	1.0A
TO-220	1.0A	1.5A	45W	70	2.7	1.0A	1.5A

* I_D (continuous) is limited by max rated T_j.

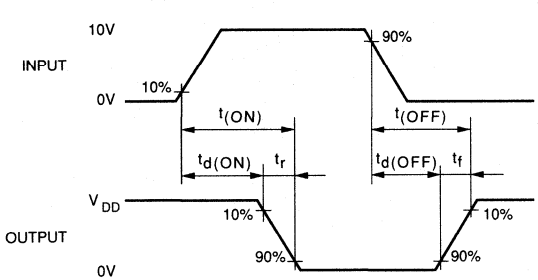
Electrical Characteristics (@ 25°C unless otherwise specified)

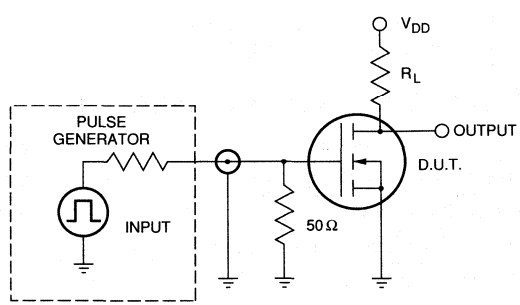
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN0645	450			V	V_{GS} = 0, I_D = 2mA
		VN0650	500				
$V_{GS(th)}$	Gate Threshold Voltage		2		4	V	V_{GS} = V_{DS}, I_D = 2mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				-4.5	mV/°C	V_{GS} = V_{DS}, I_D = 2mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			0.8		A	V_{GS} = 5V, V_{DS} = 25V
			0.5	1.1			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			15		Ω	V_{GS} = 5V, I_D = 100mA
				13	16		V_{GS} = 10V, I_D = 400mA
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature				0.75	%/°C	V_{GS} = 10V, I_D = 400mA
G_{FS}	Forward Transconductance		100			m℧	V_{DS} = 25V, I_D = 400mA
C_{ISS}	Input Capacitance			120	130	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			20	75		
C_{RSS}	Reverse Transfer Capacitance			10	20		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = 25V, I_D = 0.4A, R_S = 50Ω
t_r	Rise Time				10		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				10		
V_{SD}	Diode Forward Voltage Drop				1.8	V	V_{GS} = 0, I_{SD} = 0.4A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 0.4A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

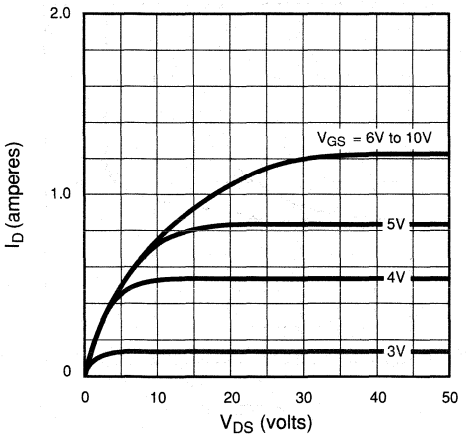
Switching Waveforms and Test Circuit



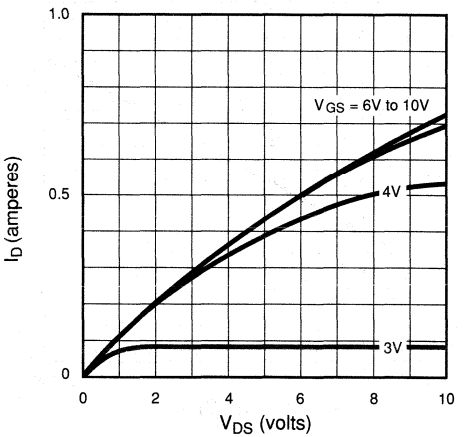


Typical Performance Curves

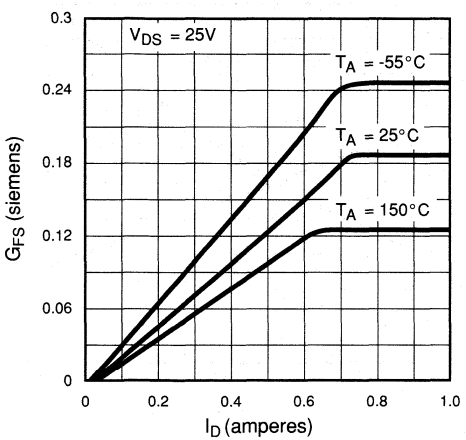
Output Characteristics



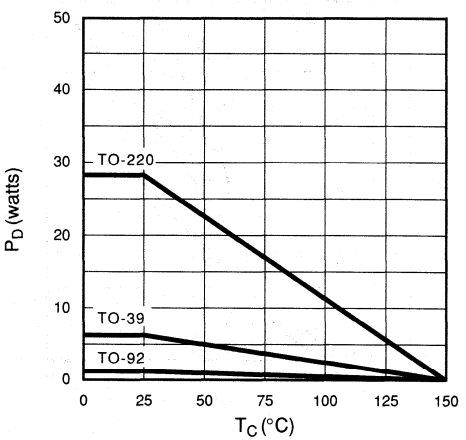
Saturation Characteristics



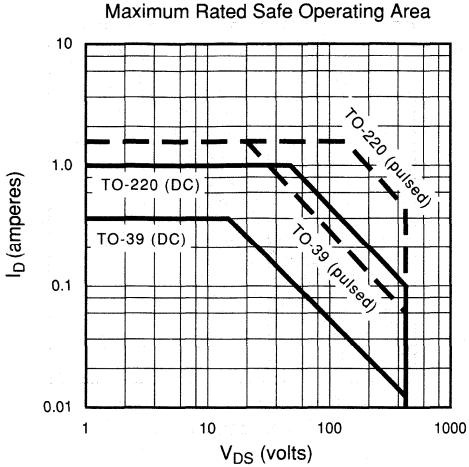
Transconductance vs. Drain Current



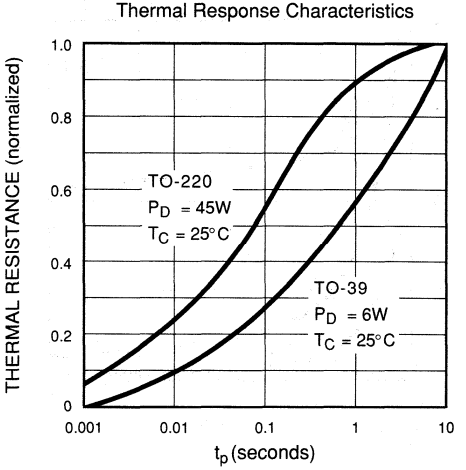
Power Dissipation vs. Case Temperature



Maximum Rated Safe Operating Area

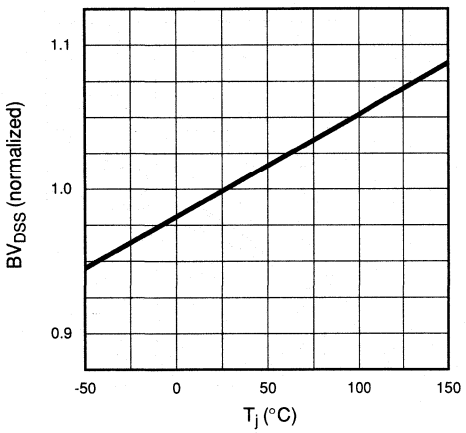


Thermal Response Characteristics

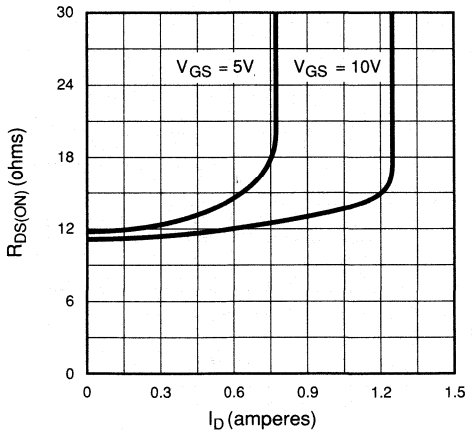


8

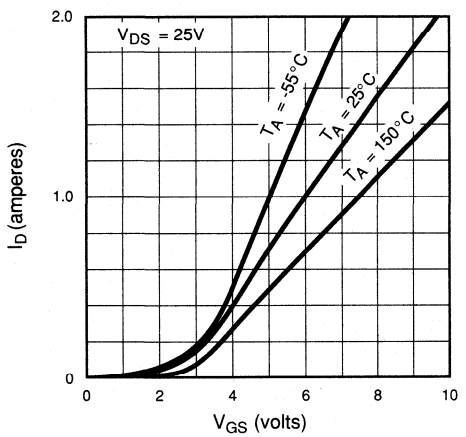
BV$_{DSS}$ Variation with Temperature



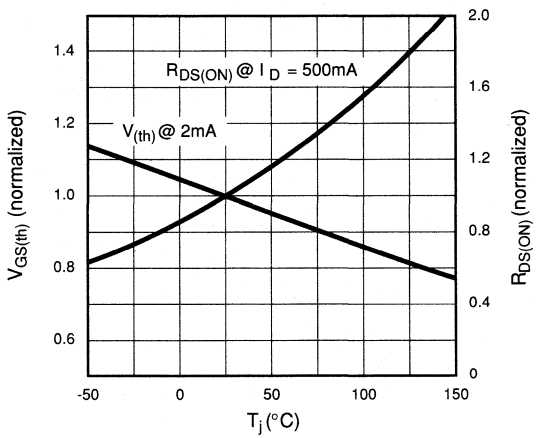
On-Resistance vs. Drain Current



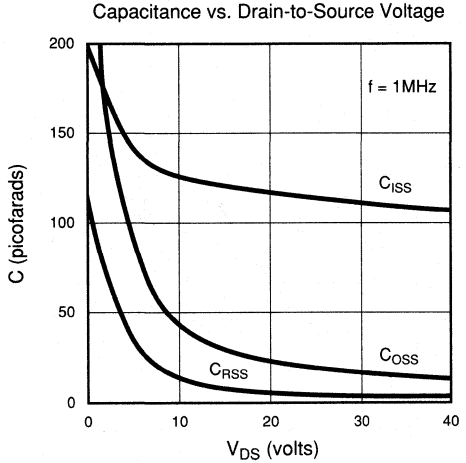
Transfer Characteristics



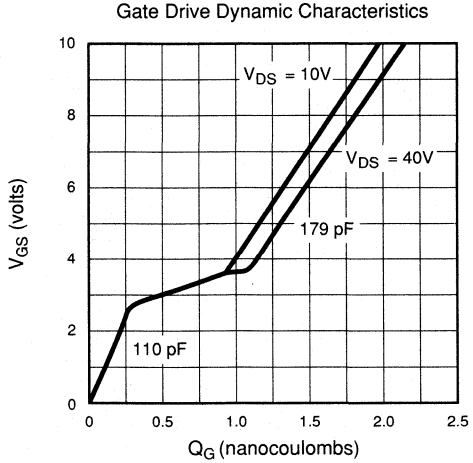
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package			
			TO-39	TO-92	TO-220	Dice†
550V	20Ω	0.25A	VN0655N2	VN0655N3	VN0655N5	VN0655ND
600V	20Ω	0.25A	VN0660N2	VN0660N3	VN0660N5	VN0660ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

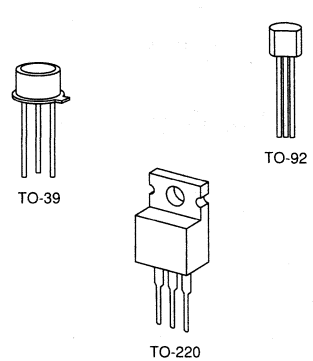
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



Notes 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	0.35A	1.0A	6W	125	21	0.25A	1.0A
TO-92	0.15A	0.5A	1W	170	125	0.15A	0.5A
TO-220	0.75A	1.5A	25W	70	5	0.6A	1.0A

* I_D (continuous) is limited by max rated T_j.

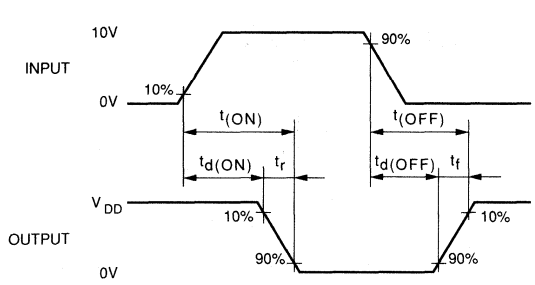
Electrical Characteristics (@ 25°C unless otherwise specified)

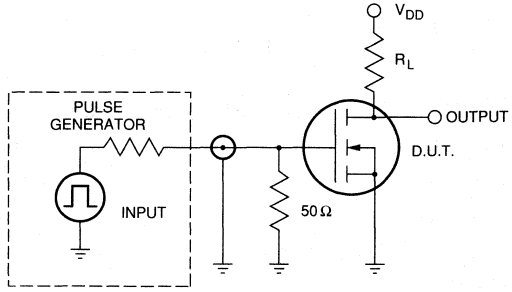
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN0655	550			V	V_{GS} = 0, I_D = 2mA
		VN0660	600				
$V_{GS(th)}$	Gate Threshold Voltage		2		4	V	V_{GS} = V_{DS}, I_D = 2mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				-4.5	mV/°C	V_{GS} = V_{DS}, I_D = 2mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			0.8		A	V_{GS} = 5V, V_{DS} = 25V
			.25	1			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			19		Ω	V_{GS} = 5V, I_D = 100mA
				15	20		V_{GS} = 10V, I_D = 100mA
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature				0.75	%/°C	V_{GS} = 10V, I_D = 100mA,
G_{FS}	Forward Transconductance		50			m℧	V_{DS} = 25V, I_D = 100mA
C_{ISS}	Input Capacitance			85	130	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			25	75		
C_{RSS}	Reverse Transfer Capacitance			10	20		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = 25V, I_D = 0.4A, R_S = 50Ω
t_r	Rise Time				10		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				10		
V_{SD}	Diode Forward Voltage Drop				1.8	V	V_{GS} = 0, I_{SD} = 100mA
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 100mA

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

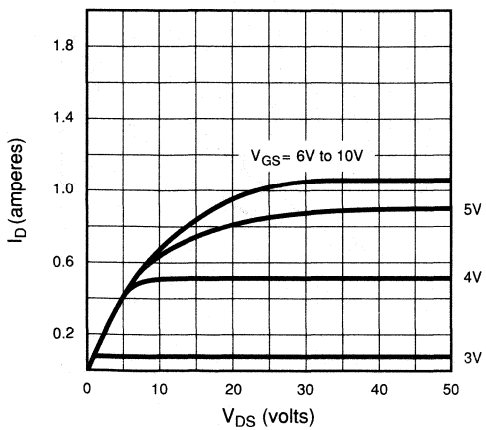
Switching Waveforms and Test Circuit



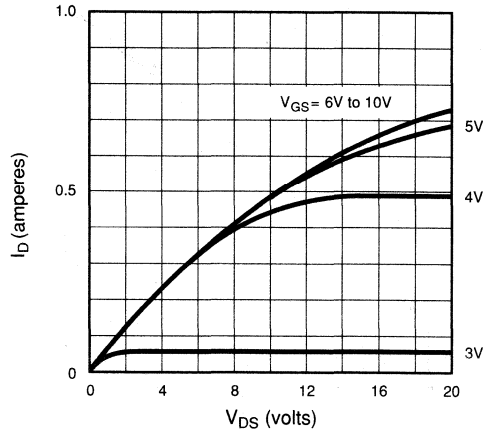


Typical Performance Curves

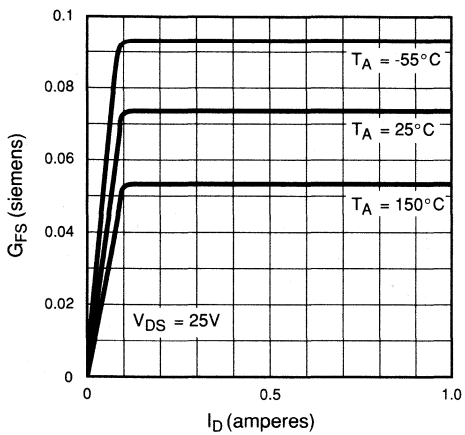
Output Characteristics



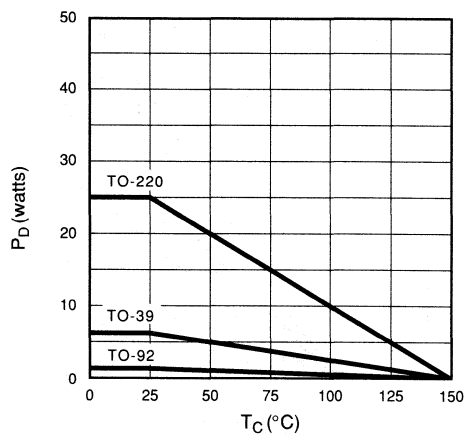
Saturation Characteristics



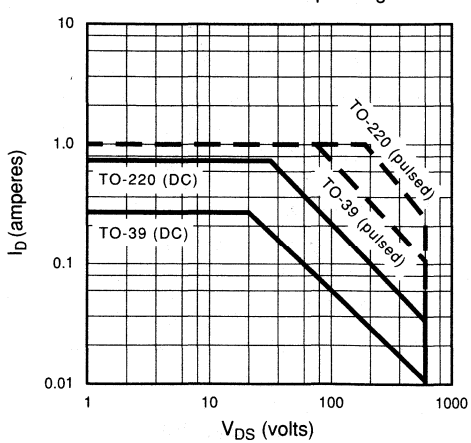
Transconductance vs. Drain Current



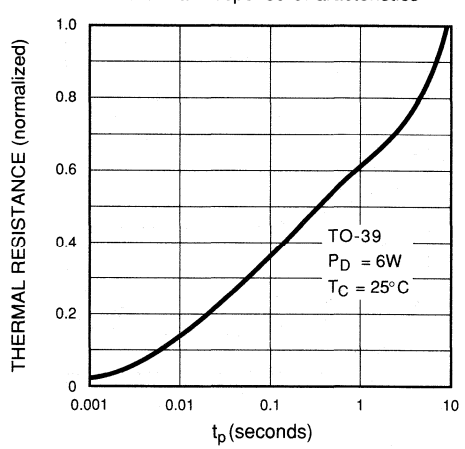
Power Dissipation vs. Case Temperature



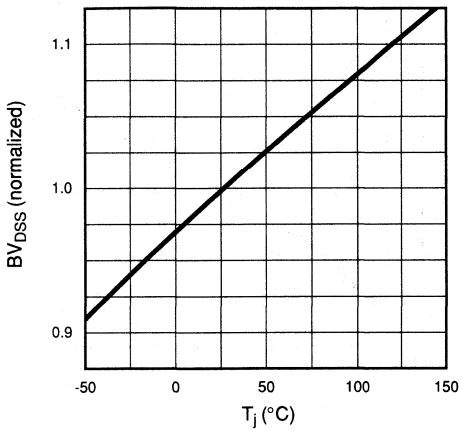
Maximum Rated Safe Operating Area



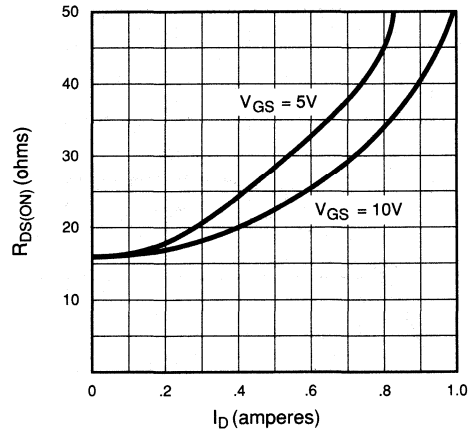
Thermal Response Characteristics



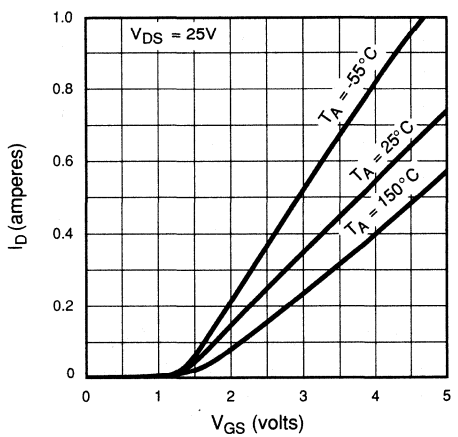
BV$_{DSS}$ Variation with Temperature



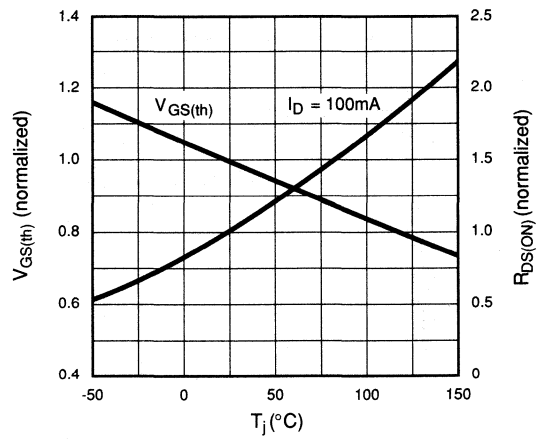
On-Resistance vs. Drain Current



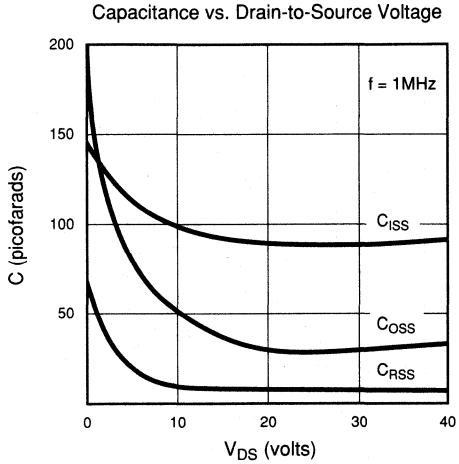
Transfer Characteristics



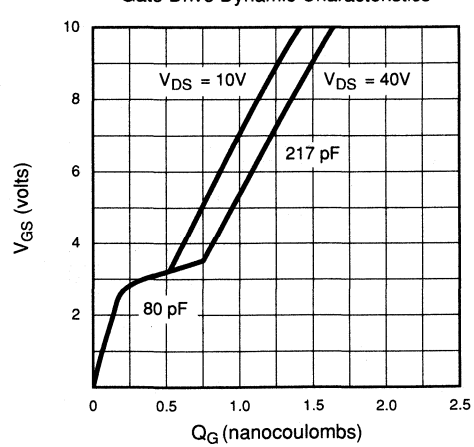
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package
			TO-92
60V	3Ω	1.5A	VN0606L
60V	5Ω	0.75A	VN0610LL

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	±40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

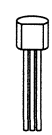
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W
TO-92	0.3A	2A	4W	312.5	51

* I_D (continuous) is limited by max rated T_j.

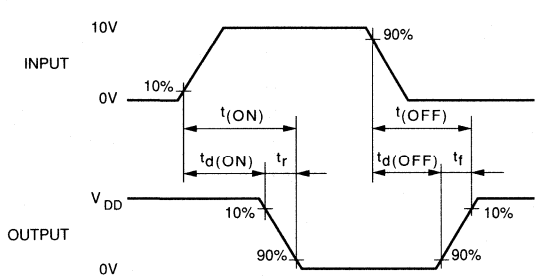
Electrical Characteristics (@ 25°C unless otherwise specified)

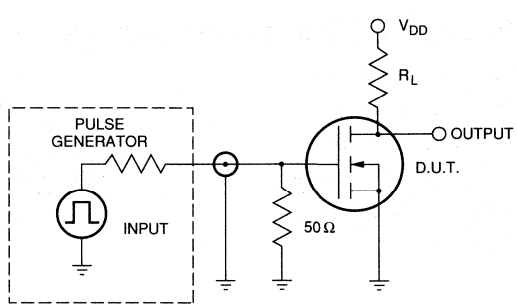
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN0610	60			V	V_{GS} = 0, I_D = 100μA
		VN0606	60				V_{GS} = 0, I_D = 10μA
$V_{GS(th)}$	Gate Threshold Voltage	VN0610	0.8		2.5	V	V_{GS} = V_{DS}, I_D = 1mA
		VN0606	0.8		2.0		
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ± 15V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	μA	V_{GS} = 0, V_{DS} = Max Rating
				500			V_{GS} = 0, V_{DS} = Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	VN0610	0.75			A	V_{GS} = 10, V_{DS} ≥ $2V_{DS(ON)}$
		VN0606	1.5				V_{GS} = 10, V_{DS} ≥ $2V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	VN0610			7.5	Ω	V_{GS} = 5V, I_D = 0.2A
		VN0610			5.0		V_{GS} = 10V, I_D = 0.5A
		VN0606			3.0		V_{GS} = 10V, I_D = 1A
G_{FS}	Forward Transconductance		170			m℧	V_{DS} ≥ $2V_{DS(ON)}$, I_D = 1A
C_{ISS}	Input Capacitance				50	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance				25		
C_{RSS}	Reverse Transfer Capacitance				5		
$t_{d(ON)}$	Turn-ON Delay Time			10		ns	V_{DD} = 25V, R_L = 23Ω, R_S = 25Ω
$t_{d(OFF)}$	Turn-OFF Delay Time			10			
V_{SD}	Diode Forward Voltage Drop	VN0610		-1.2		V	V_{GS} = 0, I_{SD} = -0.47A
		VN0606		-0.85			V_{GS} = 0, I_{SD} = -0.47A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package
			TO-92
80V	4Ω	1.5A	VN0808L

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	±40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

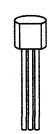
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS Power FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W
TO-92	.26A	2.0A	1W	125	26.4

* I_D (continuous) is limited by max rated T_j.

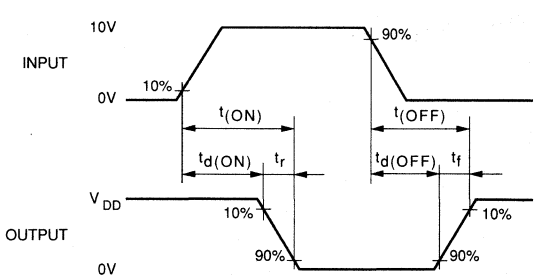
Electrical Characteristics (@ 25°C unless otherwise specified)

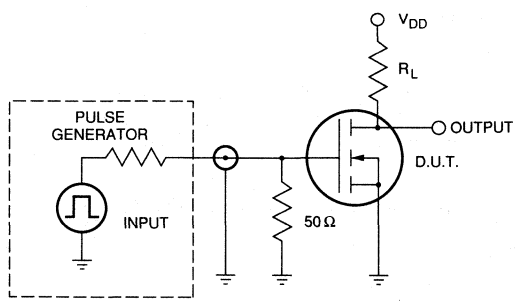
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	80			V	I_D = 10μA, V_{GS} = 0
$V_{GS(th)}$	Gate Threshold Voltage	0.8		2.0	V	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage			100	nA	V_{GS} = ±15V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			10	μA	V_{GS} = 0, V_{DS} = Max Rating
				500		V_{GS} = 0, V_{DS} = Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	1.5			A	V_{GS} = 10V, V_{DS} ≥ 2 $V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			4	Ω	V_{GS} = 10V, I_D = 1A
G_{FS}	Forward Transconductance	170			m℧	V_{DS} = 10V, I_D = 0.2A
C_{ISS}	Input Capacitance			50	pF	V_{GS} = 0V, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			40		
C_{RSS}	Reverse Transfer Capacitance			10		
$t_{d(ON)}$	Turn-ON Delay Time			10	ns	V_{DD} = 15V, I_D = 0.6A R_S = 50Ω
$t_{d(OFF)}$	Turn-OFF Delay Time			10		
V_{SD}	Diode Forward Voltage Drop		-0.85		V	I_{SD} = -0.35A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300μs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
			TO-52	TO-92
60V	5Ω	0.5A	VN10KN9	VN10KN3

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ TTL/CMOS compatibility
- ☐ Low input capacitance
- ☐ Fast switching speeds
- ☐ Reliable TO-92 package compatible with auto-insertion
- ☐ Complements VP01A P-Channel devices

Applications

- ☐ Inductive load driver
- ☐ Display driver
- ☐ Line driver
- ☐ Analog switch
- ☐ Alternative to VN0106N3

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

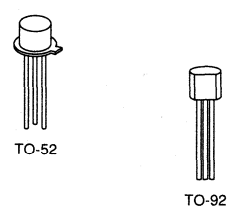
Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options

(Note 1)



Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)[1,2]	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}	I_{DRM}
TO-52	0.3A	1.0A	1.0W	170	125	1.5A	3.0A
TO-92	0.3A	1.0A	1.0W	170	125	1.5A	3.0A

Notes:
1. I_D (continuous) is limited by max rated T_j.
2. VN0106N3 can be used if an I_D (continuous) of 0.5 is needed.

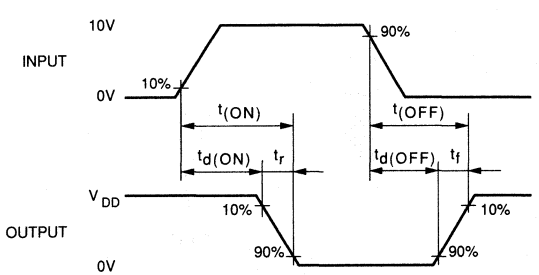
Electrical Characteristics (@ 25°C unless otherwise specified)

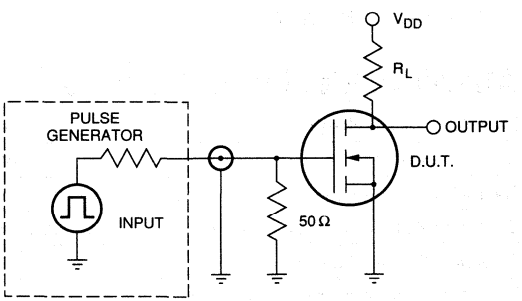
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN10K	60			V	V_{GS} = 0, I_D = 100µA
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2.5	V	V_{GS} = V_{DS}, I_D = 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.8		mV/°C	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = 10V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = 40V
$I_{D(ON)}$	ON-State Drain Current		0.25			A	V_{GS} = 5V, V_{DS} = 25V
			0.75				V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance				7.5	Ω	V_{GS} = 5V, I_D = 0.2A
					5.0	Ω	V_{GS} = 10V, I_D = 0.5A
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature			0.7		%/°C	V_{GS} = 10V, I_D = 500mA,
G_{FS}	Forward Transconductance		100			m℧	V_{DS} = 25V, I_D = 500mA
C_{ISS}	Input Capacitance			48	60	pF	V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			16	25		
C_{RSS}	Reverse Transfer Capacitance			2	5		
$t_{d(ON)}$	Turn-ON Delay Time				5	ns	V_{DD} = 25V, I_D = 0.5A, R_S = 50Ω
t_r	Rise Time				5		
$t_{d(OFF)}$	Turn-OFF Delay Time				5		
t_f	Fall Time				5		
V_{SD}	Diode Forward Voltage Drop			0.8		V	V_{GS} = 0, I_{SD} = 0.5A
t_{rr}	Reverse Recovery Time			160		ns	V_{GS} = 0, I_{SD} = 0.5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

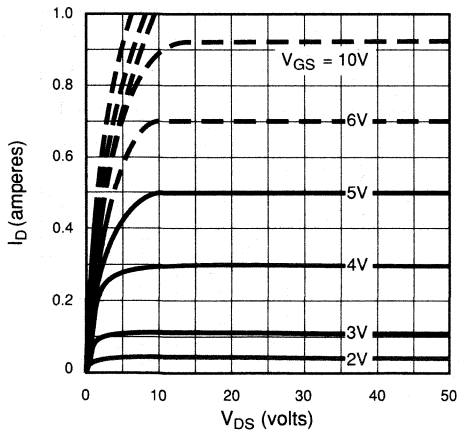
Switching Waveforms and Test Circuit



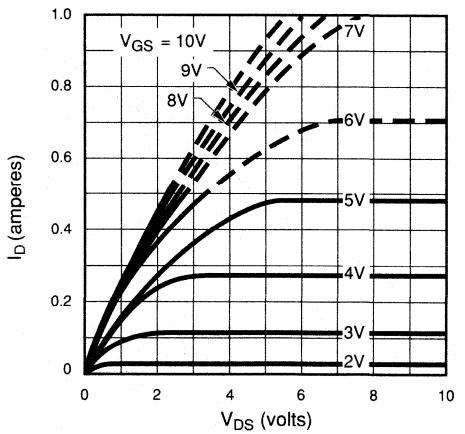


Typical Performance Curves

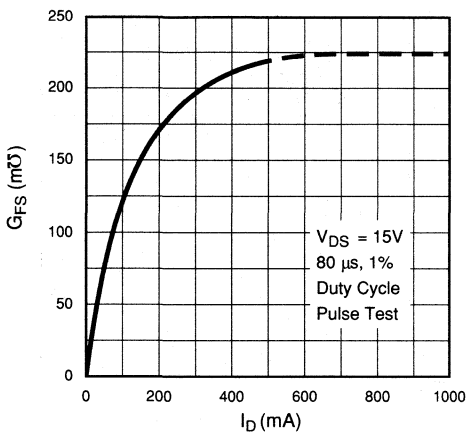
Output Characteristics



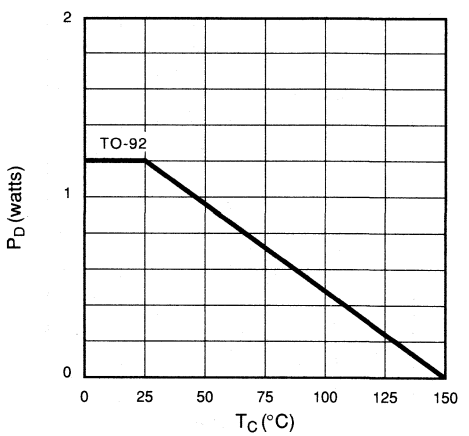
Saturation Characteristics



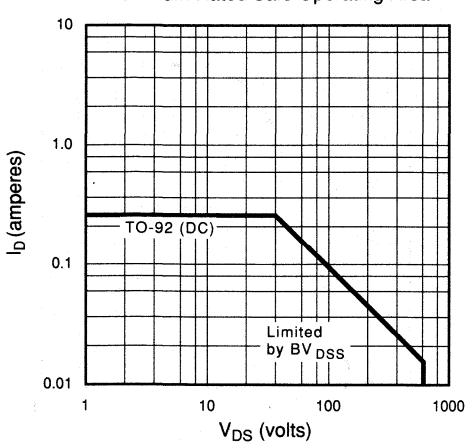
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

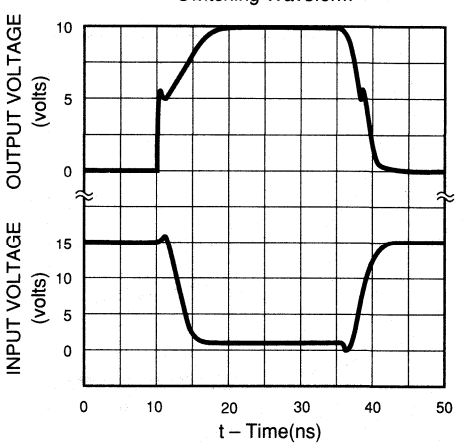


Maximum Rated Safe Operating Area

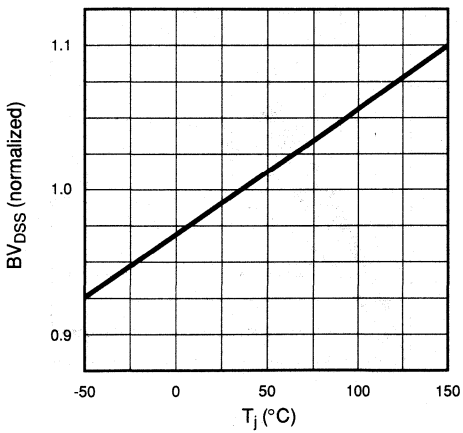


Pulsed Condition: 300µs, 2% dutycycle

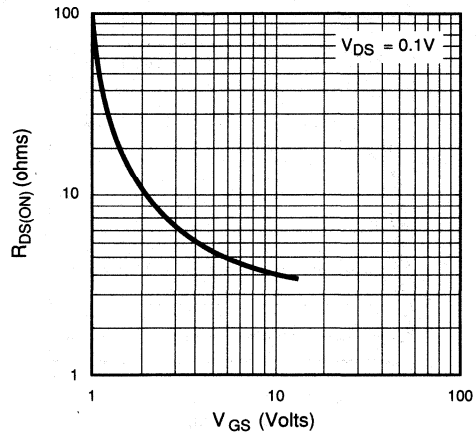
Switching Waveform



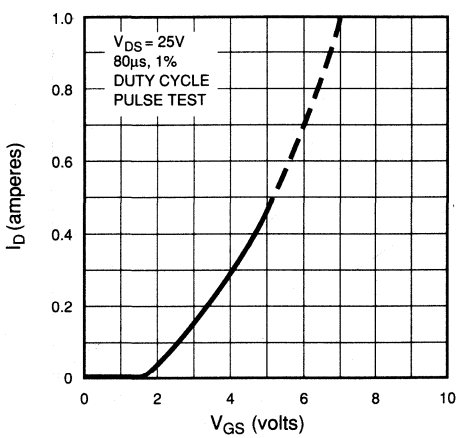
BV$_{DSS}$ Variation with Temperature



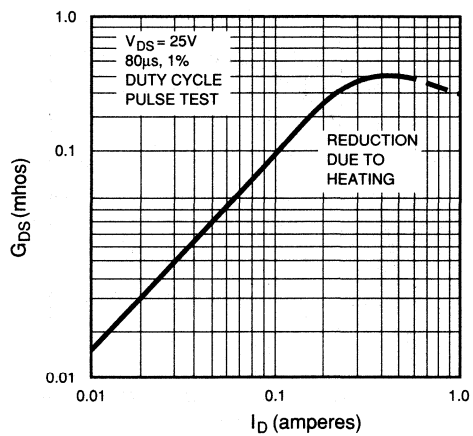
On-Resistance vs. Gate-to-Source Voltage



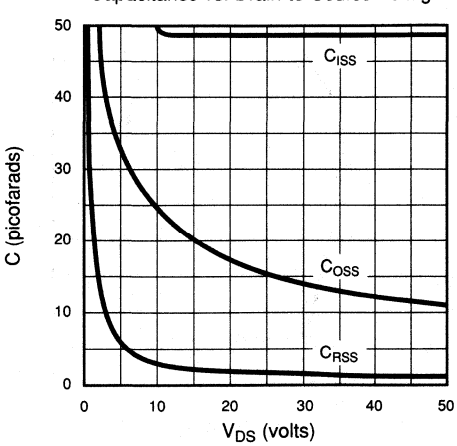
Transfer Characteristics



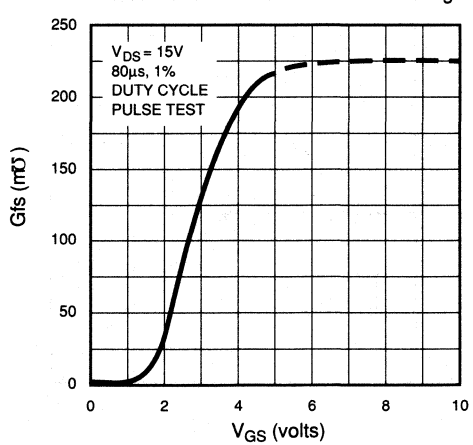
Output Conductance vs Drain Current



Capacitance vs. Drain-to-Source Voltage



Transconductance vs Gate-Source Voltage



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-220	Dice†
60V	0.7Ω	8.0A	VN1106N2	VN1106N5	VN1106ND
100V	0.7Ω	8.0A	VN1110N2	VN1110N5	VN1110ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

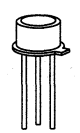
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

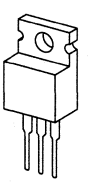
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-39



TO-220

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	2.5A	6A	6W	125	20.8	2.5A	6A
TO-220	7.0A	18A	45W	70	2.7	7.0A	18A

* I_D (continuous) is limited by max rated T_j.

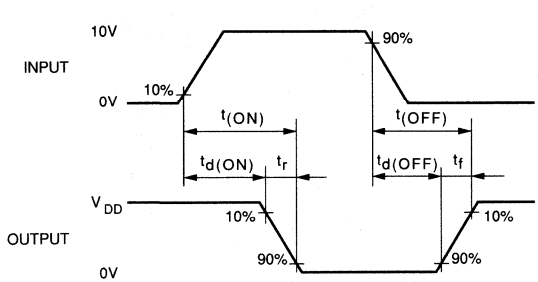
Electrical Characteristics (@ 25°C unless otherwise specified)

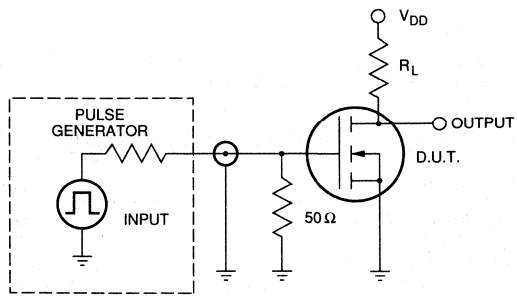
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN1110	100			V	V_{GS} = 0, I_D = 5mA
		VN1106	60				
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2.4	V	V_{GS} = V_{DS}, I_D = 2mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-4	-6	mV/°C	V_{GS} = V_{DS}, I_D = 2mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				50	µA	V_{GS} = 0, V_{DS} = Max Rating
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		3	5		A	V_{GS} = 5V, V_{DS} = 25V
			8	18			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			0.7	1.0	Ω	V_{GS} = 5V, I_D = 3A
				0.4	0.7		V_{GS} = 10V, I_D = 5A
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature			0.3	0.8	%/°C	V_{GS} = 10V, I_D = 5A
G_{FS}	Forward Transconductance		1	2		℧	V_{DS} = 25V, I_D = 3A
C_{ISS}	Input Capacitance			240	350	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			150	200		
C_{RSS}	Reverse Transfer Capacitance			16	25		
$t_{d(ON)}$	Turn-ON Delay Time			10	45	ns	V_{DD} = 25V, I_D = 3A, R_S = 50Ω
t_r	Rise Time			5	10		
$t_{d(OFF)}$	Turn-OFF Delay Time			35	45		
t_f	Fall Time			20	35		
V_{SD}	Diode Forward Voltage Drop			1.2	1.6	V	V_{GS} = 0, I_{SD} = 5A
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = 1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

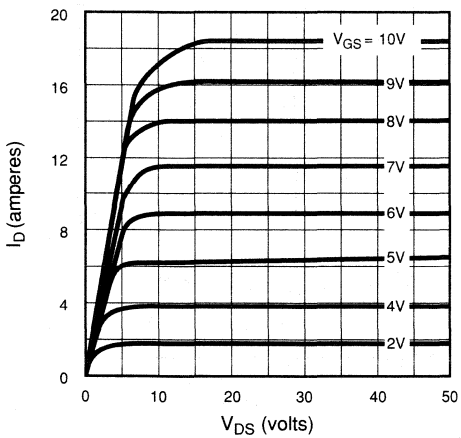
Switching Waveforms and Test Circuit



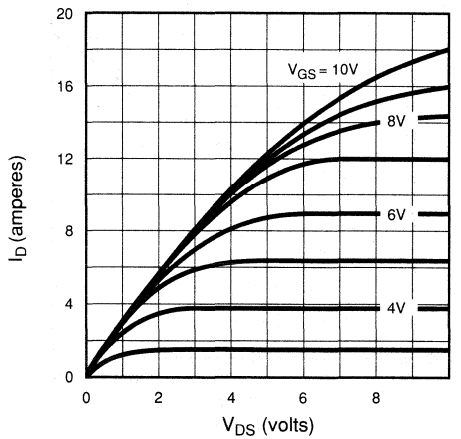


Typical Performance Curves

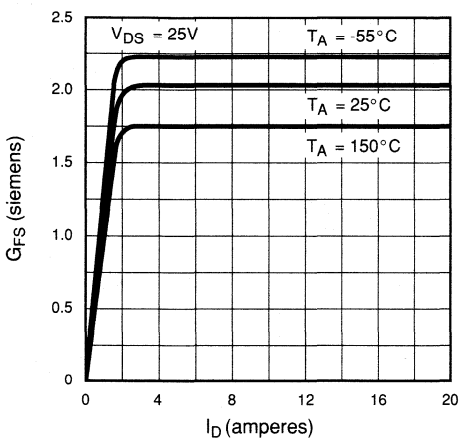
Output Characteristics



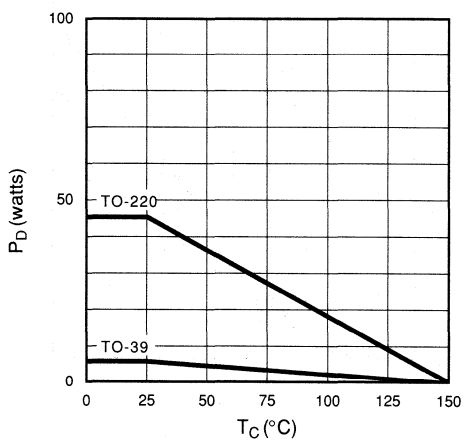
Saturation Characteristics



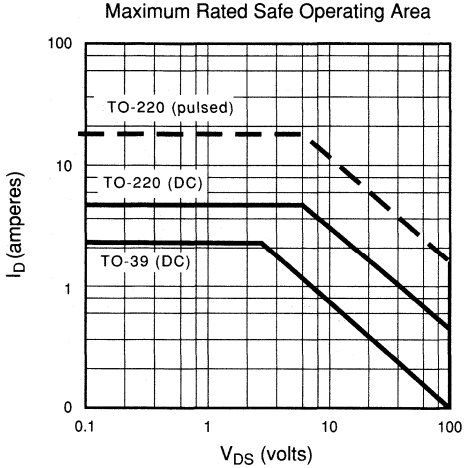
Transconductance vs. Drain Current



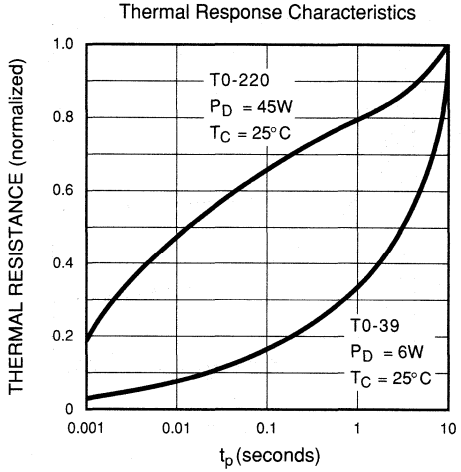
Power Dissipation vs. Case Temperature



Maximum Rated Safe Operating Area

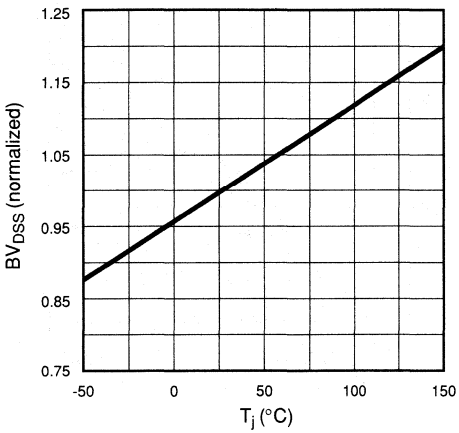


Thermal Response Characteristics

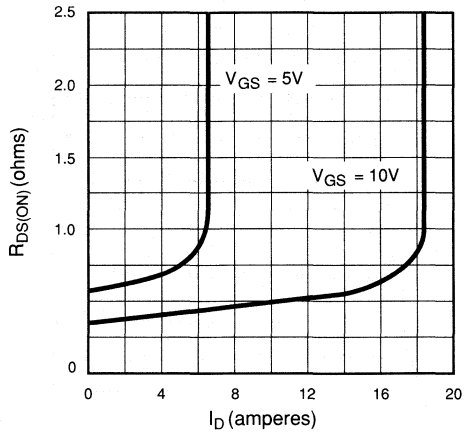


8

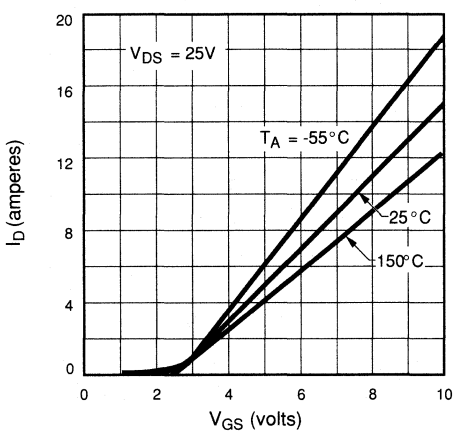
BV$_{DSS}$ Variation with Temperature



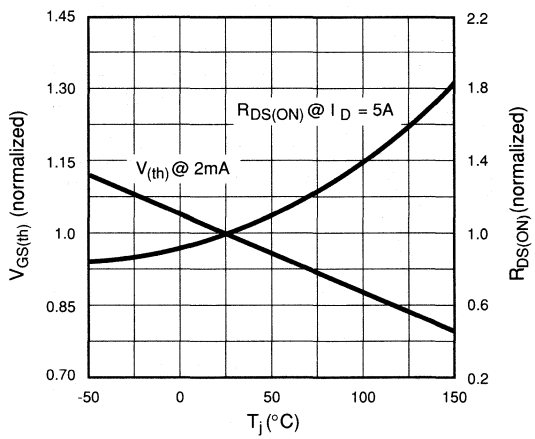
On-Resistance vs. Drain Current



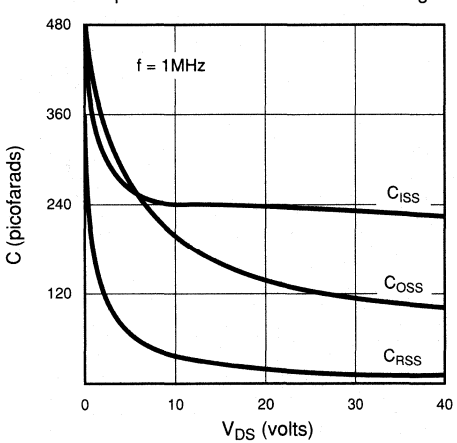
Transfer Characteristics



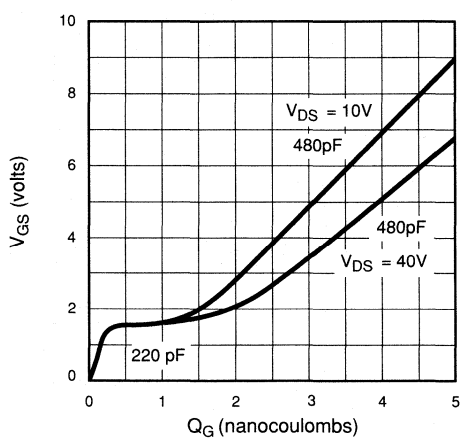
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-220	Dice†
160V	3Ω	2.0A	VN1116N2	VN1116N5	VN1116ND
200V	3Ω	2.0A	VN1120N2	VN1120N5	VN1120ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

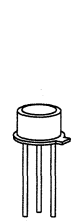
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

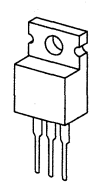
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-39



TO-220

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	1A	2.5A	4W	33	31	1A	2.5A
TO-220	2A	3.5A	45W	11.4	2.7	2A	3.5A

* I_D (continuous) is limited by max rated T_j.

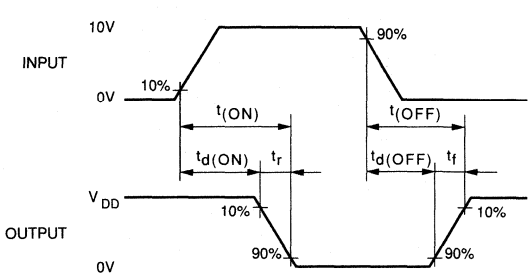
Electrical Characteristics (@ 25°C unless otherwise specified)

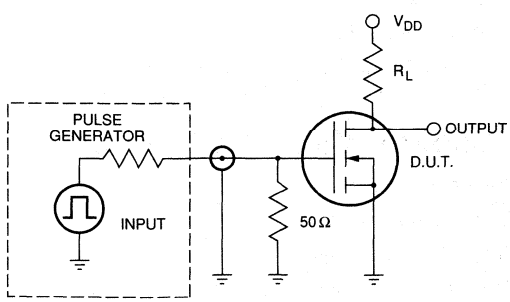
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN1116	160			V	VGS = 0, ID = 5mA
		VN1120	200				
$V_{GS(th)}$	Gate Threshold Voltage		1		3	V	$V_{GS} = V_{DS}$, I_D = 5mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.5	-6	mV/°C	$V_{GS} = V_{DS}$, I_D = 5mA
I_{GSS}	Gate Body Leakage				100	nA	$V_{GS} = \pm 20V$, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				50	µA	V_{GS} = 0, V_{DS} = Max Rating
					5	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		1	2.8		A	V_{GS} = 5V, V_{DS} = 25V
			2	3.8			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			3.5	4	Ω	V_{GS} = 5V, I_D = 0.5A
				2.5	3		V_{GS} = 10V, I_D = 1A
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature			0.6	1	%/°C	V_{GS} = 10V, I_D = 1A
G_{FS}	Forward Transconductance		0.2	0.4		m℧	V_{DS} = 25V, I_D = 0.5A
C_{ISS}	Input Capacitance			280	350	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			60	150		
C_{RSS}	Reverse Transfer Capacitance			20	30		
$t_{d(ON)}$	Turn-ON Delay Time			20	30	ns	V_{DD} = 25V, I_D = 2A, R_S = 50Ω
t_r	Rise Time			3	10		
$t_{d(OFF)}$	Turn-OFF Delay Time			32	40		
t_f	Fall Time			8	15		
V_{SD}	Diode Forward Voltage Drop			0.7	1.0	V	V_{GS} = 0, I_{SD} = 100mA
t_{rr}	Reverse Recovery Time			400		ns	V_{GS} = 0, I_{SD} = 0.1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

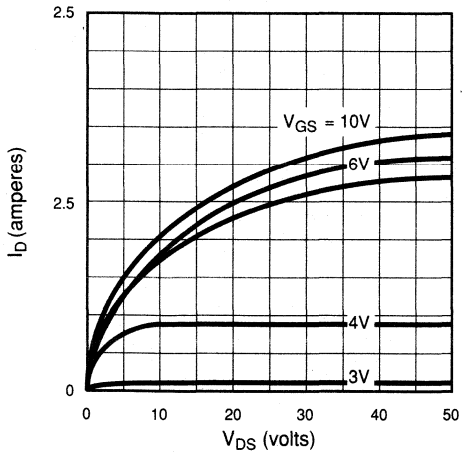
Switching Waveforms and Test Circuit



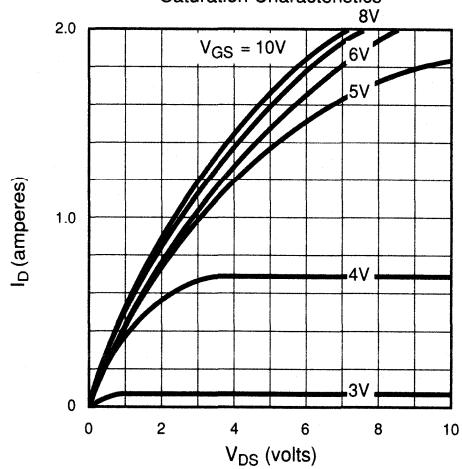


Typical Performance Curves

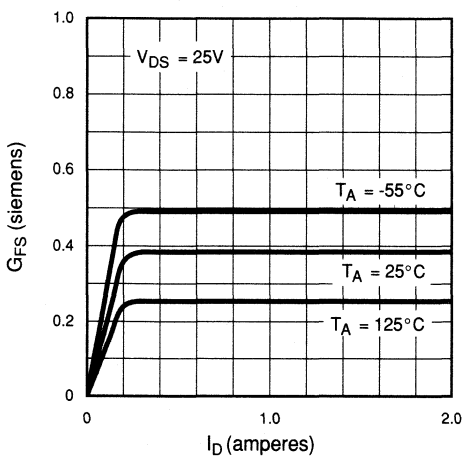
Output Characteristics



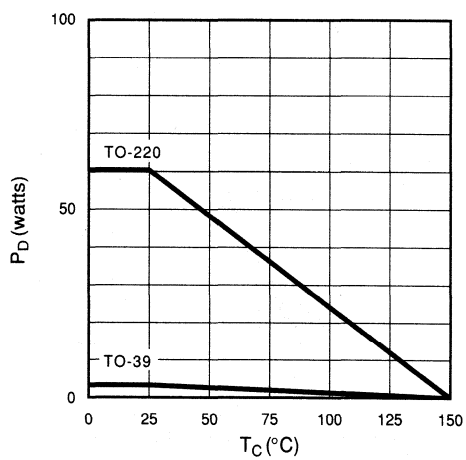
Saturation Characteristics



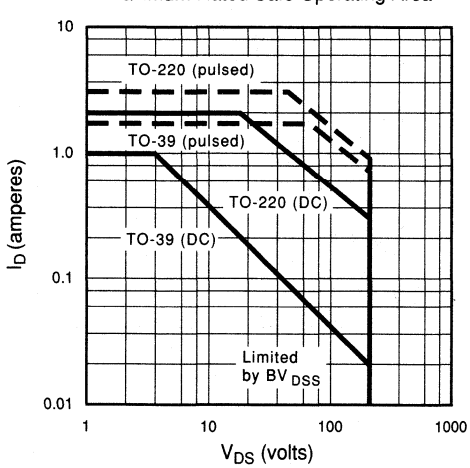
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

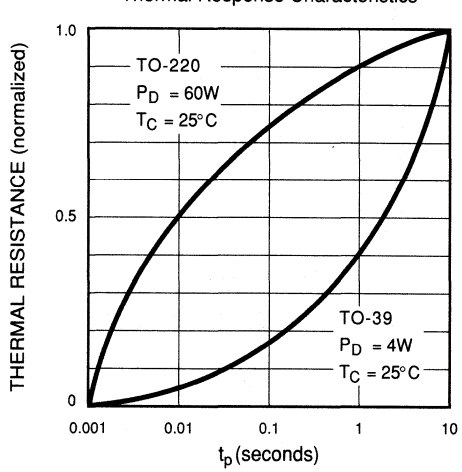


Maximum Rated Safe Operating Area

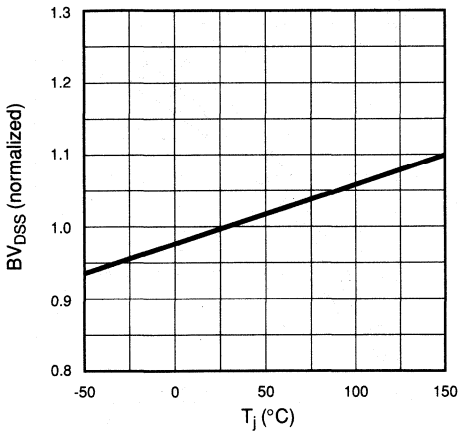


Pulsed Condition: 300 µs, 2% duty cycle

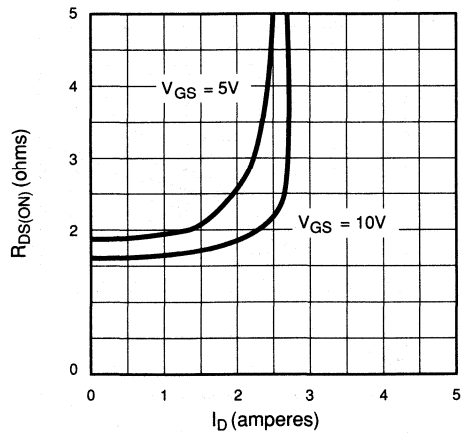
Thermal Response Characteristics



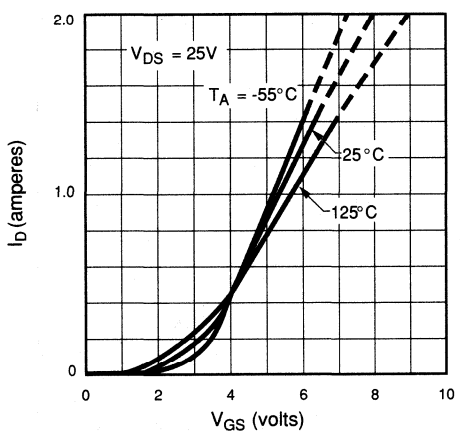
BV$_{DSS}$ Variation with Temperature



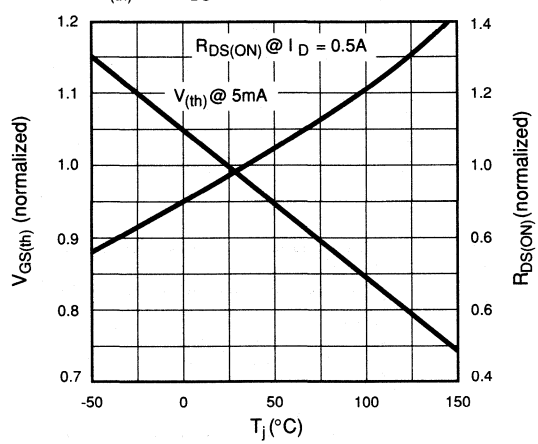
On-Resistance vs. Drain Source Current



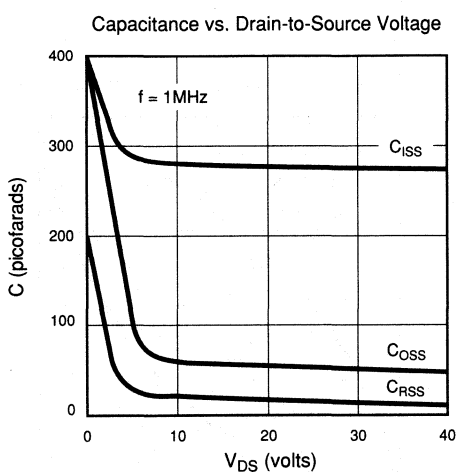
Transfer Characteristics



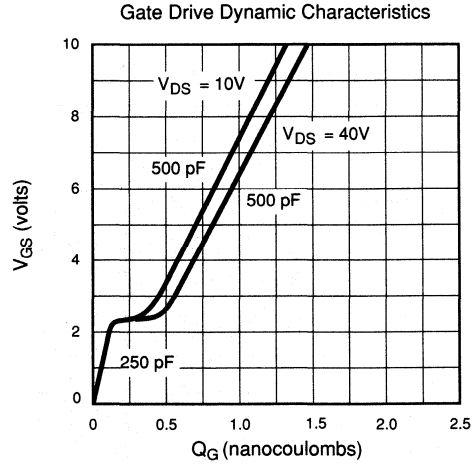
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-220	Dice†
40V	0.3Ω	20A	VN1204N2	VN1204N5	VN1204ND
60V	0.3Ω	20A	VN1206N2	VN1206N5	VN1206ND
100V	0.3Ω	20A	VN1210N2	VN1210N5	VN1210ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

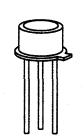
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

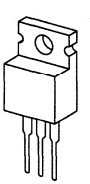
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-39



TO-220

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-39	3.5A	15A	6.5W	125	20	3.5A	15A
TO-220	9A	35A	45W	70	2.75	9A	35A

* I_D (continuous) is limited by max rated T_j.

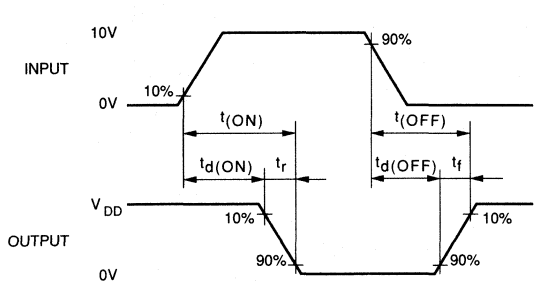
Electrical Characteristics (@ 25°C unless otherwise specified)

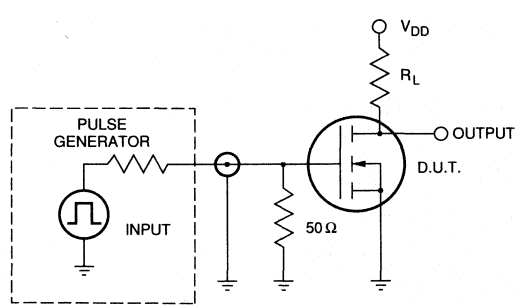
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN1210	100			V	V_{GS} = 0, I_D = 10mA
		VN1206	60				
		VN1204	40				
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2.4	V	V_{GS} = V_{DS}, I_D = 10mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-4.3	-5.5	mV/°C	V_{GS} = V_{DS}, I_D = 10mA
I_{GSS}	Gate Body Leakage			1	100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				100	µA	V_{GS} = 0, V_{DS} = Max Rating
					10	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		5	13		A	V_{GS} = 5V, V_{DS} = 25V
			20	35			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			0.22	0.45	Ω	V_{GS} = 5V, I_D = 2A
				0.2	0.3		V_{GS} = 10V, I_D = 10A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.85	1.2	%/°C	V_{GS} = 10V, I_D = 10A
G_{FS}	Forward Transconductance		4.0			℧	V_{DS} = 25V, I_D = 5A
C_{ISS}	Input Capacitance			700	850	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			300	350		
C_{RSS}	Reverse Transfer Capacitance			45	75		
$t_{d(ON)}$	Turn-ON Delay Time			8	20	ns	V_{DD} = 25V, I_D = 5A, R_S = 50Ω
t_r	Rise Time			8	20		
$t_{d(OFF)}$	Turn-OFF Delay Time			70	90		
t_f	Fall Time			40	60		
V_{SD}	Diode Forward Voltage Drop			1.2	1.4	V	V_{GS} = 0, I_{SD} = 10A
t_{rr}	Reverse Recovery Time			500		ns	V_{GS} = 0, I_{SD} = 1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

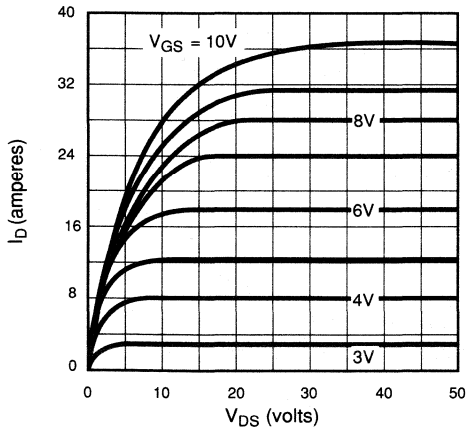
Switching Waveforms and Test Circuit



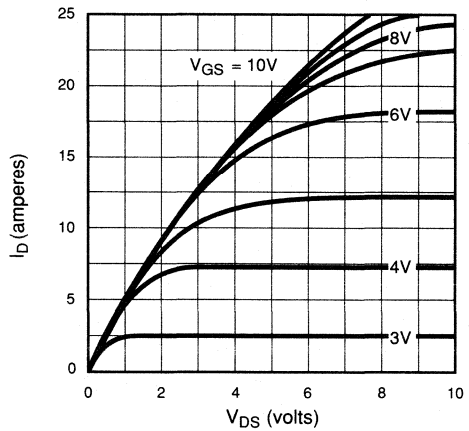


Typical Performance Curves

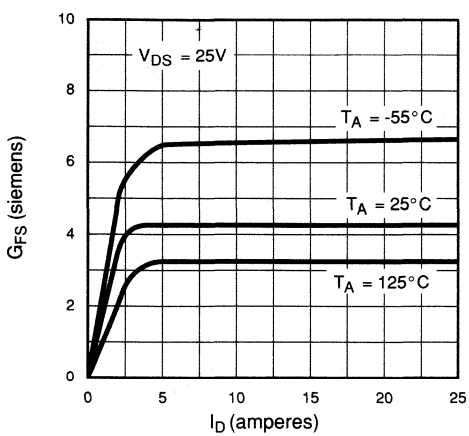
Output Characteristics



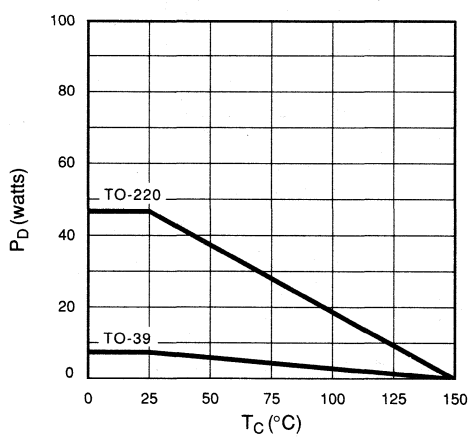
Saturation Characteristics



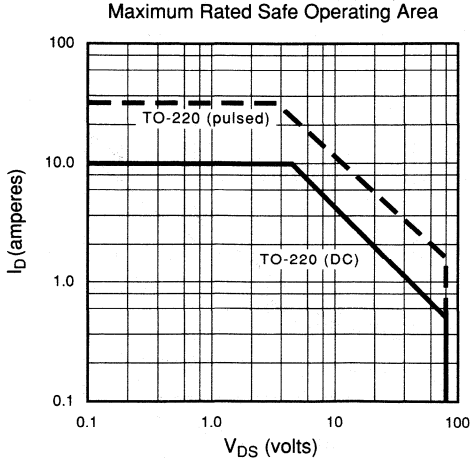
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

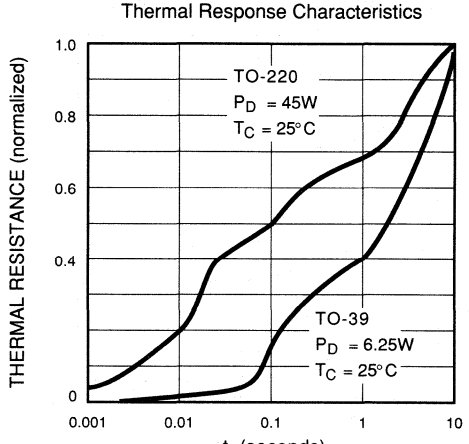


Maximum Rated Safe Operating Area



Pulsed Condition: 300 µs, 2% duty cycle

Thermal Response Characteristics



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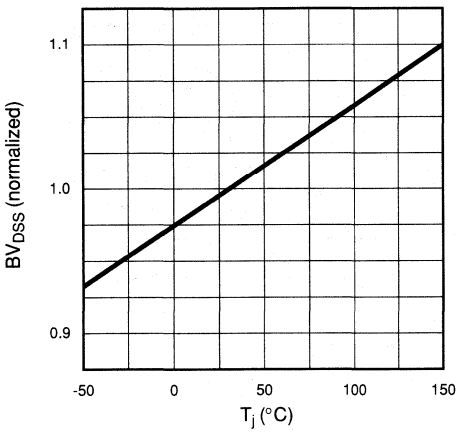
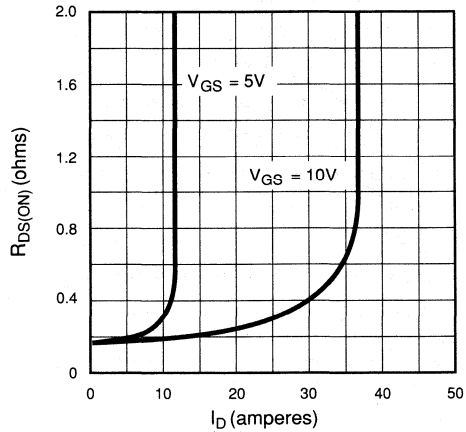
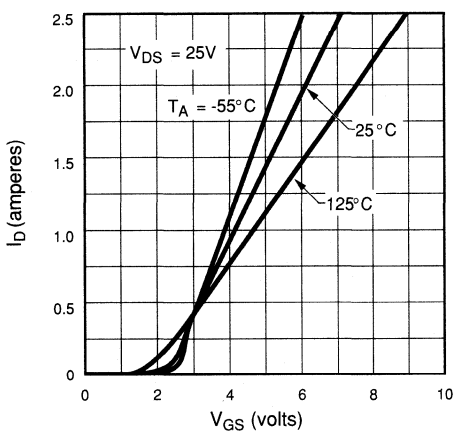
BV$_{DSS}$ Variation with Temperature



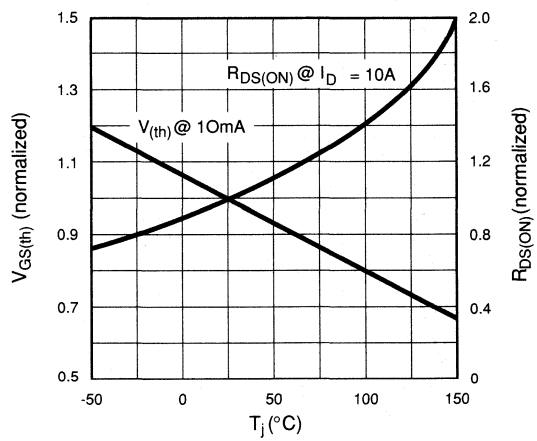
On-Resistance vs. Drain Current



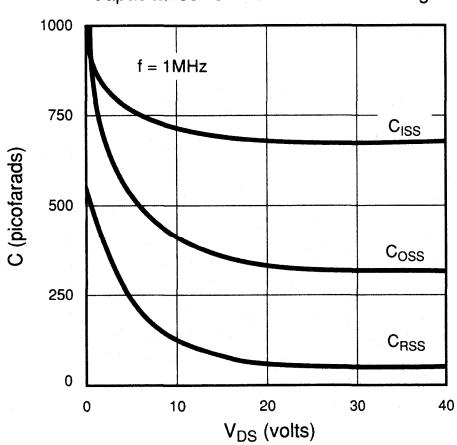
Transfer Characteristics



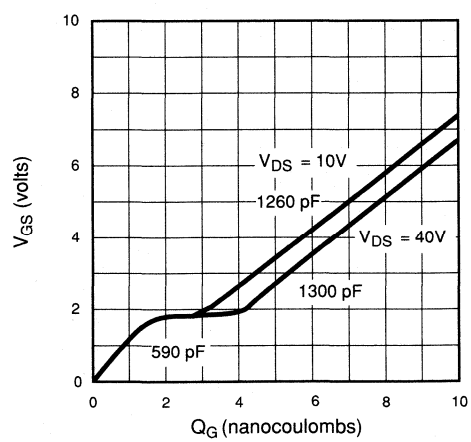
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-220	Dice†
160V	1Ω	6.0A	VN1216N2	VN1216N5	VN1216ND
200V	1Ω	6.0A	VN1220N2	VN1220N5	VN1220ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

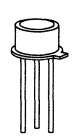
Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

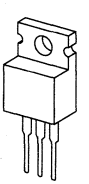
Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

8

Package Options (Note 1)



TO-39



TO-220

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	3.0A	11.0A	6.5W	125	20	3A	11A
TO-220	4.5A	13.0A	45W	70	2.75	4.5A	13A

* I_D (continuous) is limited by max rated T_j.

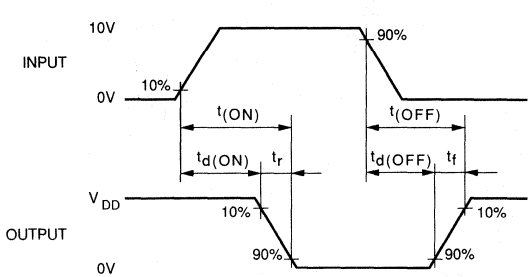
Electrical Characteristics (@ 25°C unless otherwise specified)

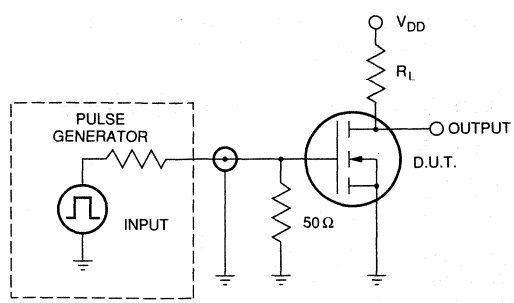
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN1220	200			V	V_{GS} = 0, I_D = 10mA
		VN1216	160				
$V_{GS(th)}$	Gate Threshold Voltage		1.0		3	V	V_{GS} = V_{DS}, I_D = 10mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.7	-4.5	mV/°C	V_{GS} = V_{DS}, I_D = 10mA
I_{GSS}	Gate Body Leakage			1	100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				100	µA	V_{GS} = 0, V_{DS} = Max Rating
					10	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		4			A	V_{GS} = 5V, V_{DS} = 25V
			8	12			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			0.7	1.5	Ω	V_{GS} = 5V, I_D = 2A
				0.6	1		V_{GS} = 10V, I_D = 2A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			1.0	1.4	%/°C	V_{GS} = 10V, I_D = 5A
G_{FS}	Forward Transconductance		2.0			℧	V_{DS} = 25V, I_D = 5A
C_{ISS}	Input Capacitance			775	850	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			180	250		
C_{RSS}	Reverse Transfer Capacitance			12	20		
$t_{d(ON)}$	Turn-ON Delay Time			8	20	ns	V_{DD} = 25V, I_D = 2A, R_S = 50Ω
t_r	Rise Time			10	20		
$t_{d(OFF)}$	Turn-OFF Delay Time			30	90		
t_f	Fall Time			30	60		
V_{SD}	Diode Forward Voltage Drop			1.3	2.5	V	V_{GS} = 0, I_{SD} = 2A
t_{rr}	Reverse Recovery Time			500		ns	V_{GS} = 0, I_{SD} = 1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

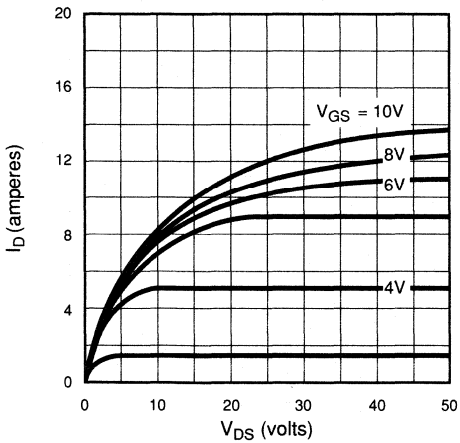
Switching Waveforms and Test Circuit



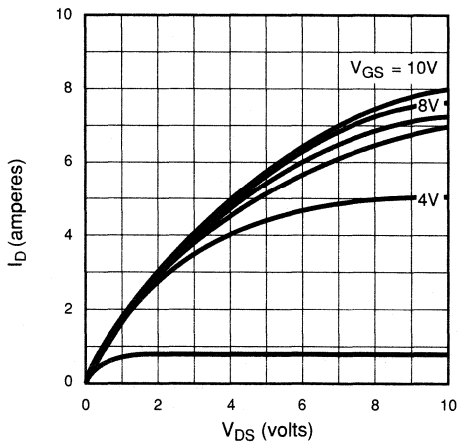


Typical Performance Curves

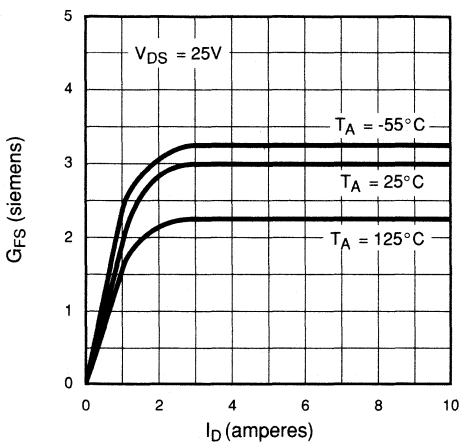
Output Characteristics



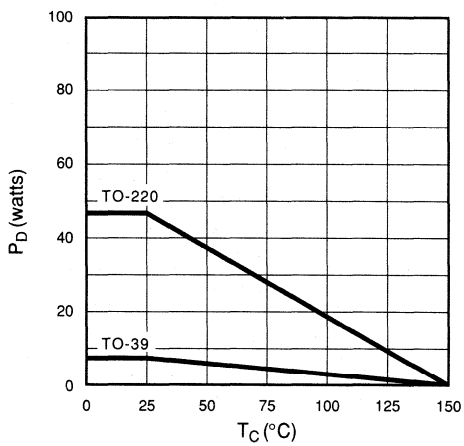
Saturation Characteristics



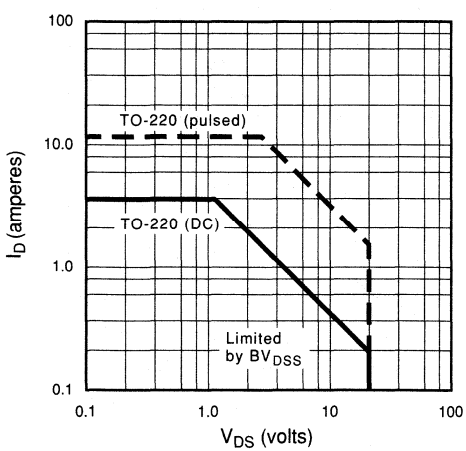
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

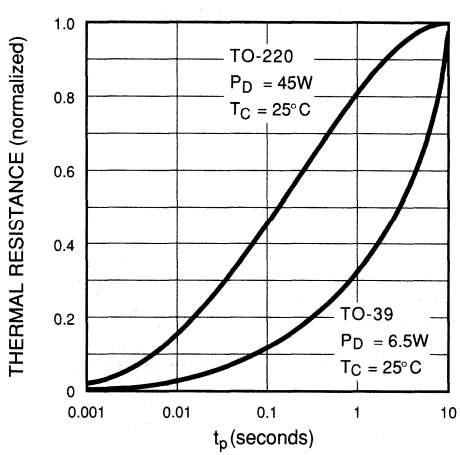


Maximum Rated Safe Operating Area



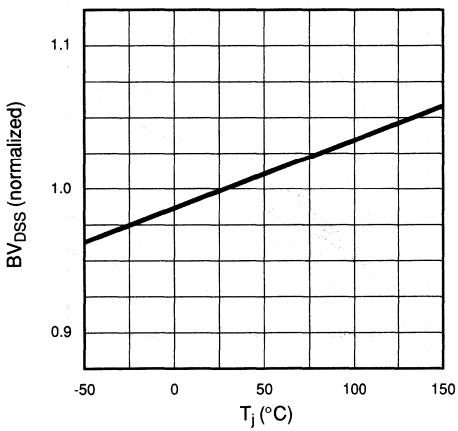
Pulsed Condition: 300 µs, 2% duty cycle

Thermal Response Characteristics

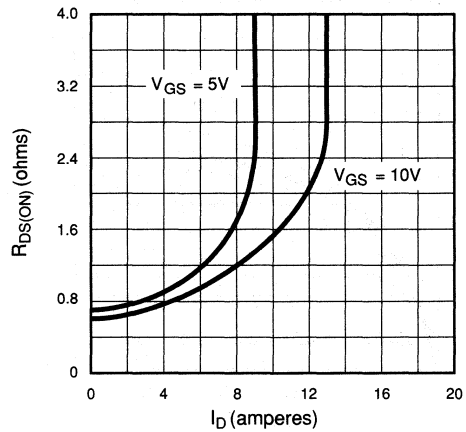


8

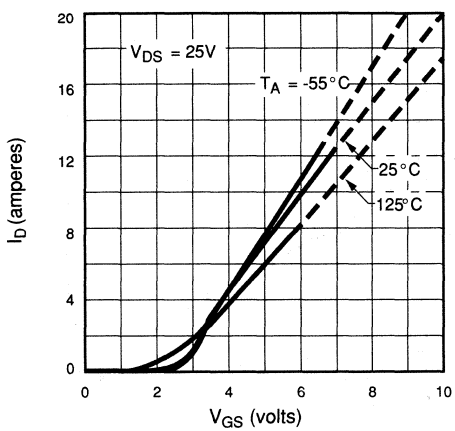
BV$_{DSS}$ Variation with Temperature



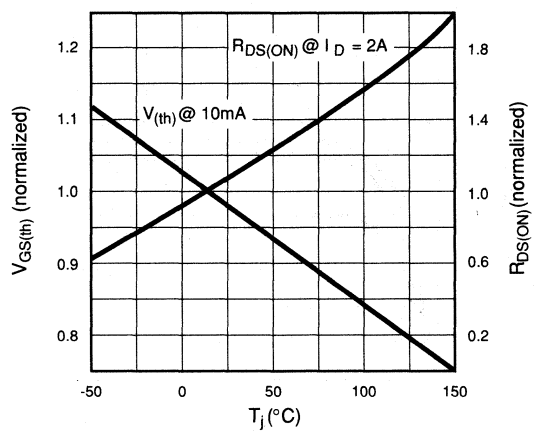
On-Resistance vs. Drain Current



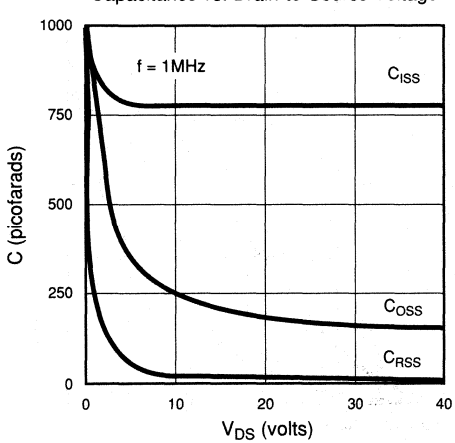
Transfer Characteristics



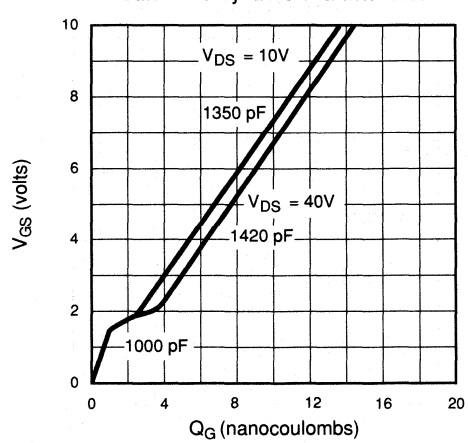
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-92	TO-220
120V	6Ω	1.0A	VN1206B	VN1206L	VN1206D
120V	10Ω	1.0A	—	VN1210L	—

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

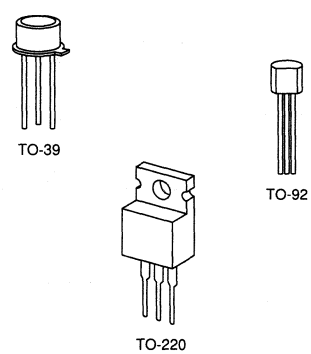
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W
TO-39	0.7A	3.0A	6.25W	170	21
TO-92	0.1A	0.6A	0.4W	312.5	21.3
TO-220	1.5A	3.0A	45W	80	6.25

* I_D (continuous) is limited by max rated T_j.

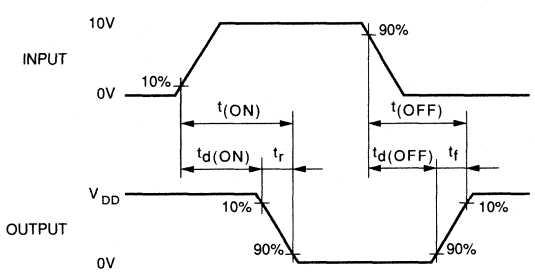
Electrical Characteristics (@ 25°C unless otherwise specified)

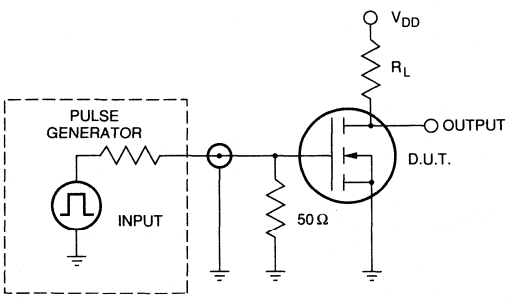
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage		120			V	V_{GS} = 0, I_D = 100µA
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2.0	V	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±15V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = Max Rating
					500		V_{GS} = 0, V_{DS} = Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		1.0			A	V_{GS} = 10V, $V_{DS} \geq 2V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	ALL			10	Ω	V_{GS} = 2.5V, I_D = 0.1A
		VN1206			6		V_{GS} = 10V, I_D = 0.5A
		VN1210			10		V_{GS} = 10V, I_D = 0.5A
G_{FS}	Forward Transconductance		300			m℧	$V_{DS} \geq 2V_{DS(ON)}$, I_D = 0.5A
C_{ISS}	Input Capacitance				125	pF	V_{GS} = 0V, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance				50		
C_{RSS}	Reverse Transfer Capacitance				20		
$t_{d(ON)}$	Turn-ON Delay Time				16	ns	V_{DD} = 60V, I_D = 0.1A, R_S = 50Ω
$t_{d(OFF)}$	Turn-OFF Delay Time				57		
V_{SD}	Diode Forward Voltage Drop	VN1210		-1.2		V	I_{SD} = -0.12A, V_{GS} = 0
		VN1206		-1.2		V	I_{SD} = -0.25A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300µs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
			TO-39	TO-92
40V	8Ω	0.5A	VN1304N2	VN1304N3
60V	8Ω	0.5A	VN1306N2	VN1306N3
100V	8Ω	0.5A	VN1310N2	VN1310N3

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

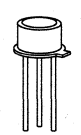
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

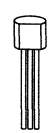
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-39



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	0.4A	1.4A	3.0W	125	41.5	0.4A	1.4A
TO-92	0.25A	1.3A	1.0W	170	125	0.25A	1.3A

* I_D (continuous) is limited by max rated T_j.

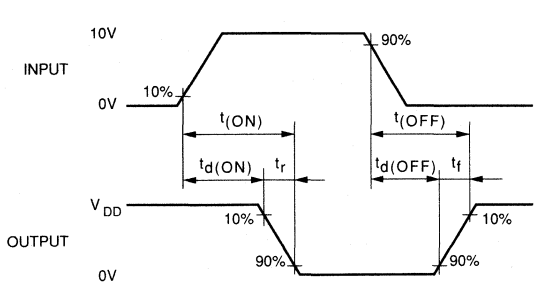
Electrical Characteristics (@ 25°C unless otherwise specified)

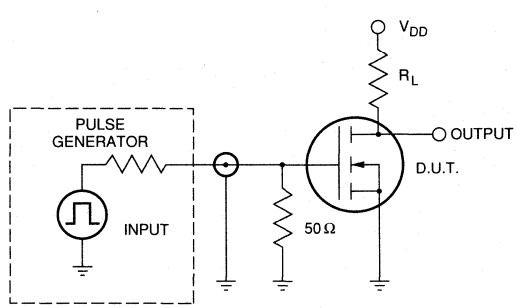
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN1310	100			V	V_{GS} = 0, I_D = 1mA
		VN1306	60				
		VN1304	40				
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2.4	V	V_{GS} = V_{DS}, I_D = 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.9	-5.0	mV/°C	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				1	µA	V_{GS} = 0, V_{DS} = Max Rating
					100	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		0.25	0.6		A	V_{GS} = 5V, V_{DS} = 25V
			0.50	1.4			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			5	15	Ω	V_{GS} = 5V, I_D = 50mA
				5	8		V_{GS} = 10V, I_D = 500mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.8	2	%/°C	V_{GS} = 10V, I_D = 500mA
G_{FS}	Forward Transconductance		120	180		℧	V_{DS} = 25V, I_D = 500mA
C_{ISS}	Input Capacitance			27	35	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			13	15		
C_{RSS}	Reverse Transfer Capacitance			3	5		
$t_{d(ON)}$	Turn-ON Delay Time			2	5	ns	V_{DD} = 25V, I_D = 500mA, R_S = 50Ω
t_r	Rise Time			2	5		
$t_{d(OFF)}$	Turn-OFF Delay Time			2	5		
t_f	Fall Time			2	5		
V_{SD}	Diode Forward Voltage Drop			1.0	1.3	V	V_{GS} = 0, I_{SD} = 1.0A
t_{rr}	Reverse Recovery Time			350		ns	V_{GS} = 0, I_{SD} = 1.0A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

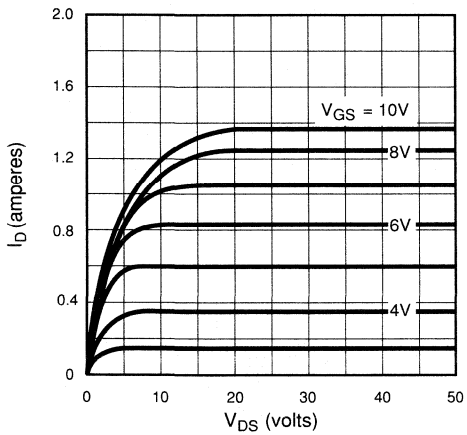
Switching Waveforms and Test Circuit



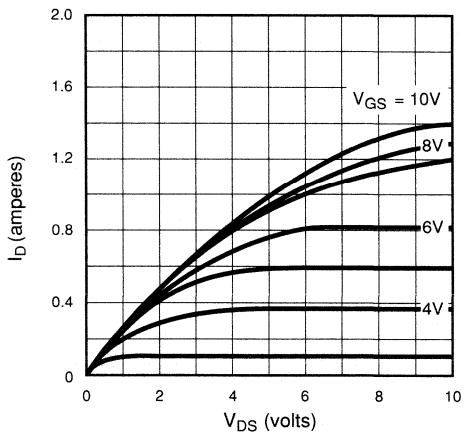


Typical Performance Curves

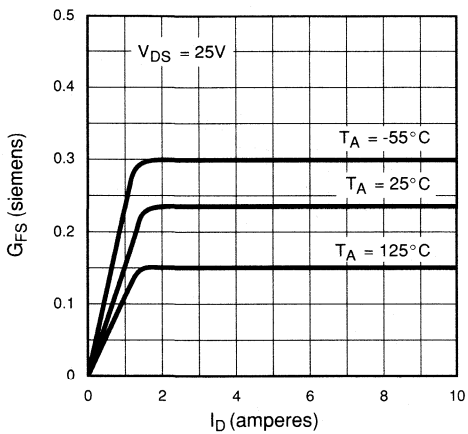
Output Characteristics



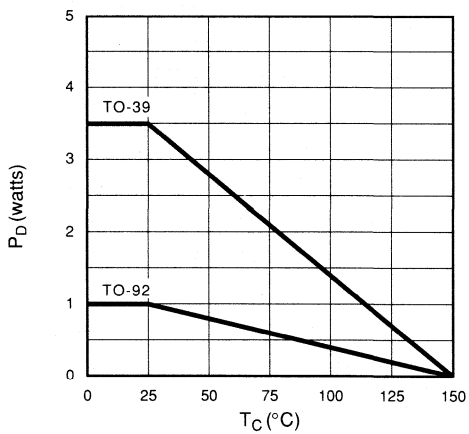
Saturation Characteristics



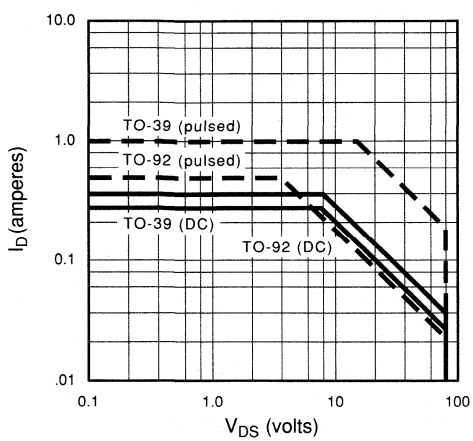
Transconductance vs. Drain Current



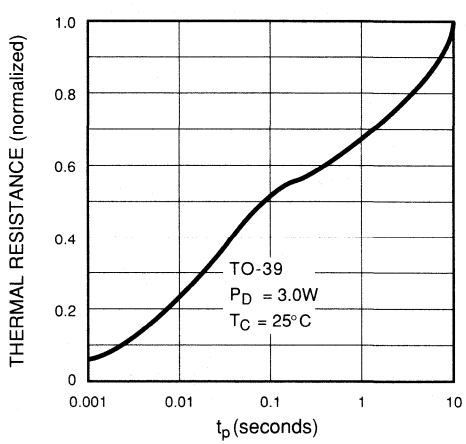
Power Dissipation vs. Case Temperature



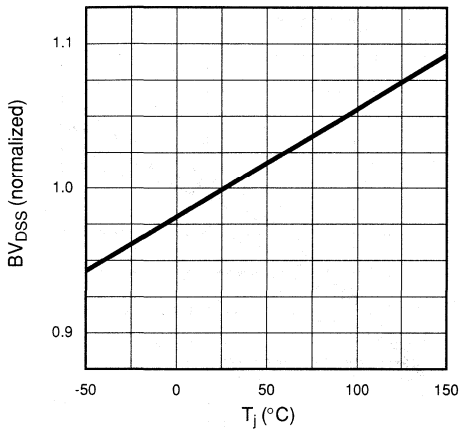
Maximum Rated Safe Operating Area



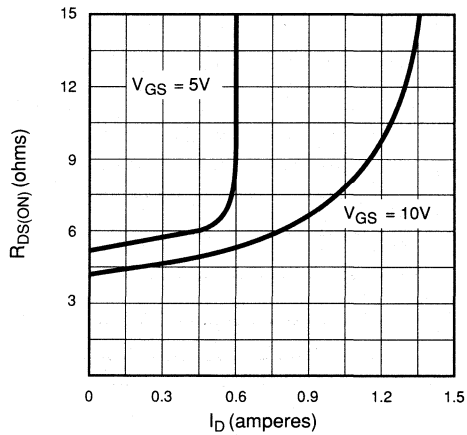
Thermal Response Characteristics



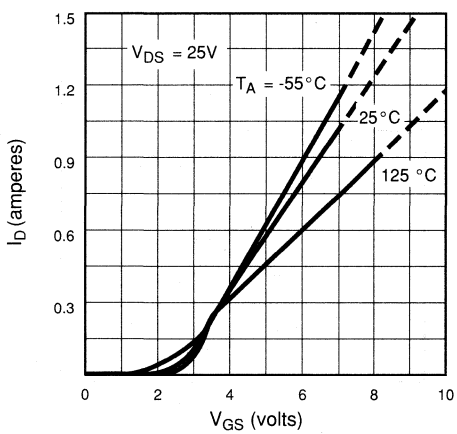
BV$_{DSS}$ Variation with Temperature



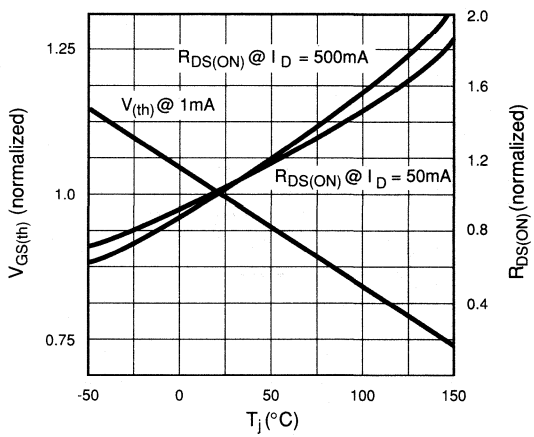
On-Resistance vs. Drain Current



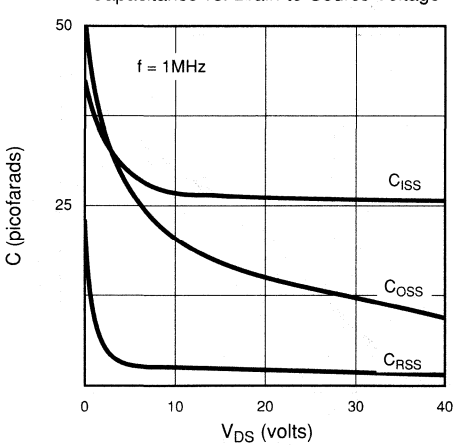
Transfer Characteristics



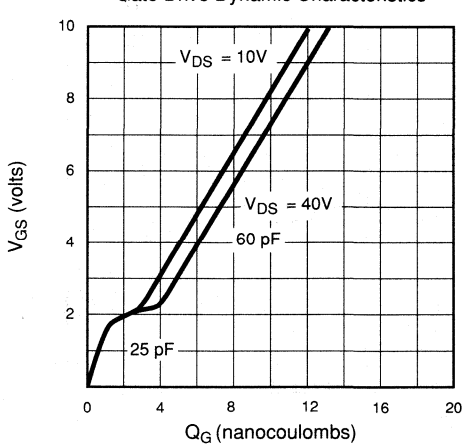
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-92	TO-220
170V	6Ω	1.0A	VN1706B	VN1706L	VN1706D
170V	10Ω	1.0A	—	VN1710L	—

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

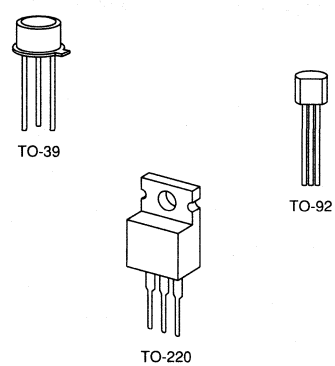
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W
TO-39	0.63A	3.0A	6.25W	170	20
TO-92	0.158A	0.6A	0.4W	312.5	21.3
TO-220	0.7A	3.0A	20W	80	6.25

* I_D (continuous) is limited by max rated T_j.

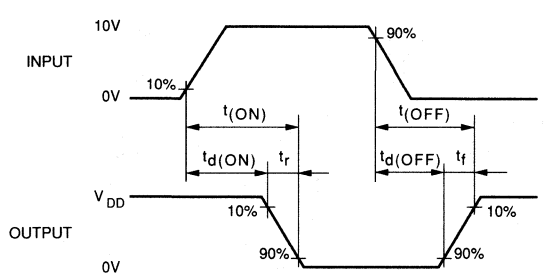
Electrical Characteristics (@ 25°C unless otherwise specified)

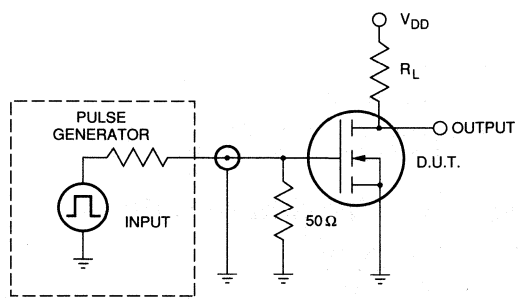
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage		170			V	V_{GS} = 0, I_D = 100µA
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2.0	V	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = 15V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = 120V
					500		V_{GS} = 0, V_{DS} = 120V T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		1.0			A	V_{GS} = 10V, $V_{DS} \geq 2V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	ALL			10	Ω	V_{GS} = 2.5V, I_D = 0.1A
		VN1710			10		V_{GS} = 10V, I_D = 0.5A
		VN1706			6		V_{GS} = 10V, I_D = 0.5A
G_{FS}	Forward Transconductance		300			m℧	$V_{DS} \geq 2V_{DS(ON)}$, I_D = 0.5A
C_{ISS}	Input Capacitance				125	pF	V_{GS} = 0V, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance				50		
C_{RSS}	Reverse Transfer Capacitance				20		
$t_{d(ON)}$	Turn-ON Delay Time				8	ns	V_{DD} = 60V, I_D = 0.1A R_S = 50Ω
$t_{d(OFF)}$	Turn-OFF Delay Time				17		
V_{SD}	Diode Forward Voltage Drop	VN1710		-1.2		V	I_{SD} = -0.19A, V_{GS} = 0
		VN1706		-1.2		V	I_{SD} = -1.4A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300µs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$V_{GS(th)}$ (max)	Order Number / Package
			TO-92
200V	10Ω	1.8V	VN2010L

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)
- ☐ Telecom Switching

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

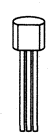
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-92	250mA	1.0A	1W	170	125	250mA	1.0A

* I_D (continuous) is limited by max rated T_j.

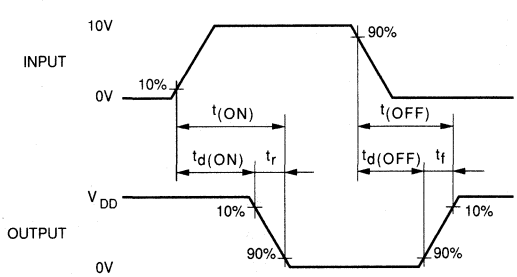
Electrical Characteristics (@ 25°C unless otherwise specified)

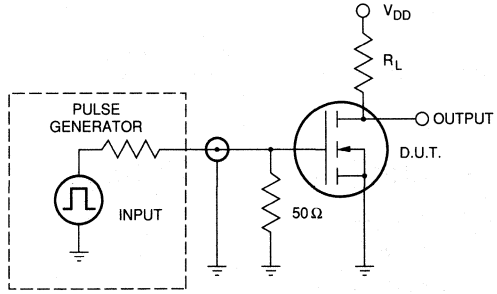
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	200			V	V_{GS} = 0, I_D= 100µA
$V_{GS(th)}$	Gate Threshold Voltage	0.6		1.8	V	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage			10	nA	V_{GS} = ±15V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			10	µA	V_{GS} = 0, V_{DS} = Max Rating
				100		V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C
$V_{DS(ON)}$	Static Drain-to-Source ON-State Voltage			0.5	V	V_{GS} = 4.5V, I_D = 50mA
				1	V	V_{GS} = 10V, I_D = 100mA
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			10	Ω	V_{GS} = 4.5V, I_D = 50mA
				10	Ω	V_{GS} = 10V, I_D = 100mA
G_{FS}	Forward Transconductance	125			m℧	V_{DS} = 25V, I_D = 0.5A
C_{ISS}	Input Capacitance			60	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			30		
C_{RSS}	Reverse Transfer Capacitance			15	ns	V_{DD} = 25V, I_D = 1A R_S = 50Ω
$t_{d(ON)}$	Turn-ON Delay Time			10		
$t_{d(OFF)}$	Turn-OFF Delay Time			30		
V_{SD}	Diode Forward Voltage Drop			1.8	V	V_{GS} = 0, I_{SD} = 250mA

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300µs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
			TO-92	Dice†
40V	0.35Ω	8A	VN2204N3	VN2204ND
60V	0.35Ω	8A	VN2206N3	VN2206ND
100V	0.35Ω	8A	VN2210N3	VN2210ND

† MIL visual screening available

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	±20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

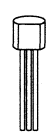
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-92	1.2A	8.0A	1.0W	170	125	1.2A	8.0A

* I_D (continuous) is limited by max rated T_j.

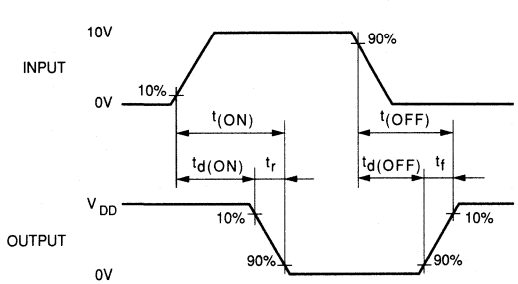
Electrical Characteristics (@ 25°C unless otherwise specified)

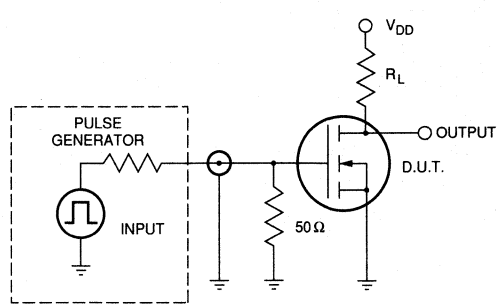
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN2204	40			V	V_{GS} = 0, I_D = 10mA
		VN2206	60				
		VN2210	100				
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2.4	V	V_{GS} = V_{DS}, I_D = 10mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-4.3	-5.5	mV/°C	V_{GS} = V_{DS}, I_D = 10mA
I_{GSS}	Gate Body Leakage			1	100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				50	µA	V_{GS} = 0, V_{DS} = Max Rating
					10	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		3	4.5		A	V_{GS} = 5V, V_{DS} = 25V
			8				V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			0.4	0.5	Ω	V_{GS} = 5V, I_D = 1A
				0.27	0.35		V_{GS} = 10V, I_D = 4A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.85	1.2	%/°C	V_{GS} = 10V, I_D = 4A
G_{FS}	Forward Transconductance		1.5	2.0		℧	V_{DS} = 25V, I_D = 2A
C_{ISS}	Input Capacitance				500	pF	V_{GS} = 0, V_{DS} = 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance				200		
C_{RSS}	Reverse Transfer Capacitance				65		
$t_{d(ON)}$	Turn-ON Delay Time			10	15	ns	V_{DD} = 25V, I_D = 4A, R_S = 50Ω
t_r	Rise Time			10	15		
$t_{d(OFF)}$	Turn-OFF Delay Time			30	50		
t_f	Fall Time			30	50		
V_{SD}	Diode Forward Voltage Drop			1.0	1.6	V	V_{GS} = 0, I_{SD} = 4A
t_{rr}	Reverse Recovery Time			500		ns	V_{GS} = 0, I_{SD} = 1A

Notes:
1: All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2: All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS Power FET

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package
			TO-92
60V	7.5Ω	0.75A	VN2222LL

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

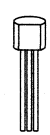
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W
TO-92	0.99A	1.0A	0.4W	312.5	51

* I_D (continuous) is limited by max rated T_j.

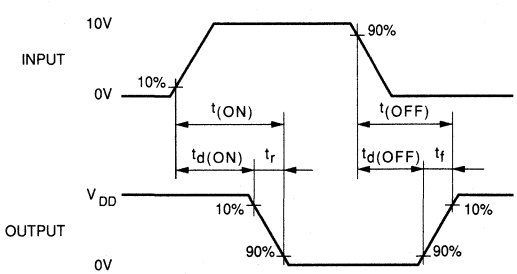
Electrical Characteristics (@ 25°C unless otherwise specified)

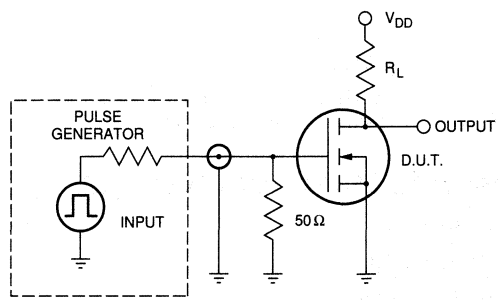
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	60			V	V_{GS} = 0, I_D= 100μA
$V_{GS(th)}$	Gate Threshold Voltage	0.6		2.5	V	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage			100	nA	V_{GS} = 15V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			10	μA	V_{GS} = 0, V_{DS} = Max Rating
				500		V_{GS} = 0, V_{DS} = 50V, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	0.75			A	V_{GS} = 10V, $V_{DS} \geq 2V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			7.5	Ω	V_{GS} = 5V, I_D = 0.2A
				7.5	Ω	V_{GS} = 10V, I_D = 0.5A
G_{FS}	Forward Transconductance	100			m℧	$V_{DS} \geq 2V_{DS(ON)}$, I_D = 0.5A
C_{ISS}	Input Capacitance			60	pF	V_{GS} = 0, V_{DS} = 15, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			25		
C_{RSS}	Reverse Transfer Capacitance			5		
$t_{d(ON)}$	Turn-ON Delay Time			10	ns	V_{DD} = 15V, I_D = 0.6A, R_S = 50Ω
$t_{d(OFF)}$	Turn-OFF Delay Time			10		
V_{SD}	Diode Forward Voltage Drop		-0.85		V	V_{GS} = 0, I_{SD} = -0.2A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300μs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-92	TO-220
240V	6Ω	1.0A	VN2406B	VN2406L	VN2406D
240V	10Ω	1.0A	—	VN2410L	—

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

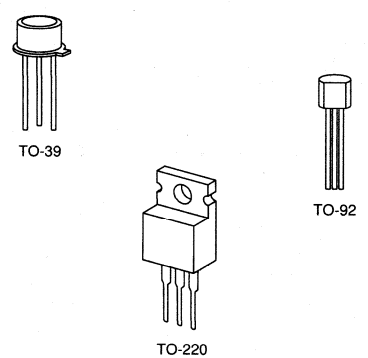
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)* @ T_C = 25°C	I_D (pulsed)* °C/W	Power Dissipation °C/W	θ_{ja}	θ_{jc}
TO-39	0.7A	3.0A	6.25W	170	21
TO-92	0.158A	0.6A	0.4W	312.5	21.3
TO-220	1.5A	3.0A	45W	80	6.25

* I_D (continuous) is limited by max rated T_j.

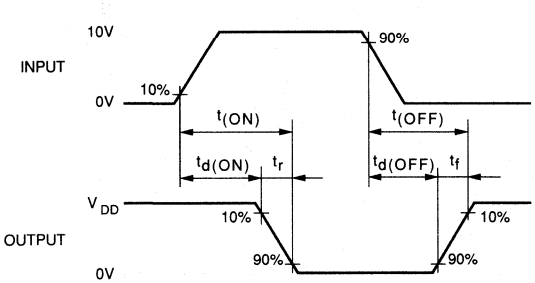
Electrical Characteristics (@ 25°C unless otherwise specified)

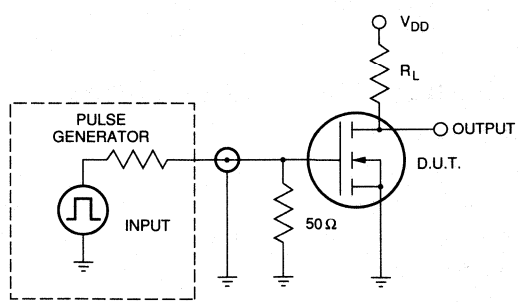
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage		240			V	V_{GS} = 0, I_D = 10mA
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2	V	V_{GS} = V_{DS}, I_D = 10mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = 15V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				10	µA	V_{GS} = 0, V_{DS} = 120V
					500		V_{GS} = 0, V_{DS} = 120V T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		1.0			A	V_{GS} = -10V, V_{DS} ≥2$V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	All			10	Ω	V_{GS} = 2.5V, I_D = 0.1A
		VN2410			10		V_{GS} = 10V, I_D = 0.5A
		VN2406			6		V_{GS} = 10V, I_D = 0.5A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			1.0	1.4	%/°C	V_{GS} = 10V, I_D = 5A
G_{FS}	Forward Transconductance		300			m℧	V_{DS} ≥2$V_{DS(ON)}$, I_D = 0.5A
C_{ISS}	Input Capacitance				125	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance				50		
C_{RSS}	Reverse Transfer Capacitance				20		
$t_{d(ON)}$	Turn-ON Delay Time				8	ns	V_{DD} = 25V I_D = 2A R_S = 50Ω
t_r	Rise Time				8		
$t_{d(OFF)}$	Turn-OFF Delay Time				18		
t_f	Fall Time				12		
V_{SD}	Diode Forward Voltage Drop	VN2410		-1.2		V	V_{GS} = 0, I_{SD} = -0.19A
		VN2406		-1.2		V	V_{GS} = 0, I_{SD} = -0.8A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$V_{GS(th)}$ (max)	Order Number / Package	
			TO-39	TO-92
350V	15Ω	1.8V	—	VN3515L
400V	12Ω	1.8V	VN4012B	VN4012L

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Telecom Switching
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 30V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

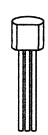
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
VN3515L	150mA	600mA	1W	170	125	150mA	600mA
VN4012L	160mA	650mA	1W	170	125	160mA	650mA

* I_D (continuous) is limited by max rated T_j.

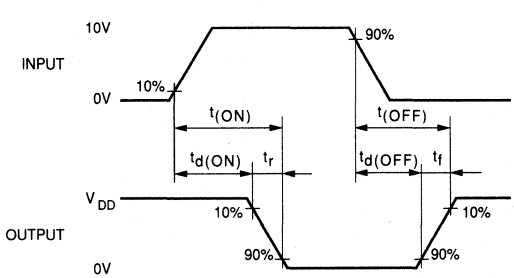
Electrical Characteristics (@ 25°C unless otherwise specified)

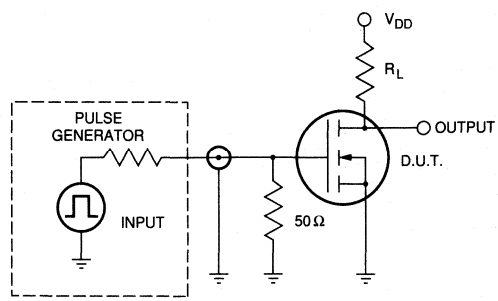
(Notes 1,2 and 3)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN3515	350			V	V_{GS} = 0, I_D = 100µA
		VN4012	400				
$V_{GS(th)}$	Gate Threshold Voltage		0.6		1.8	V	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage				10	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				1	µA	V_{GS} = 0, V_{DS} = Max Rating
					100		V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		0.15	0.3		A	V_{DS} = 10V, V_{GS} = 4.5V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	VN3515			15	Ω	V_{GS} = 4.5V, I_D = 100mA
				17	35		V_{GS} = 4.5V, I_D = 100mA, TA = 125°C
		VN4012		9.5	12		V_{GS} = 4.5V, I_D = 100mA
				17	30		V_{GS} = 4.5V, I_D = 100mA, TA = 125°C
G_{FS}	Forward Transconductance		125	350		m℧	V_{DS} =15V, I_D = 100mA
C_{ISS}	Input Capacitance				90	pF	V_{DS} = 25V, V_{GS} = 0V, f = 1MHz
C_{OSS}	Common Source Output Capacitance				20		
C_{RSS}	Reverse Transfer Capacitance				5		
$t_{d(ON)}$	Turn-ON Delay Time				20	ns	V_{DD} = 25V, I_D = 100mA, R_S = 50Ω
t_r	Rise Time				20		
$t_{d(OFF)}$	Turn-OFF Delay Time				65		
t_f	Fall Time				65		
V_{SD}	Diode Forward Voltage Drop				1.2	V	V_{GS} = 0, I_{SD} = 160mA

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.
3. See TN06D data sheet for characteristic curves.

Switching Waveforms and Test Circuit





P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package						
			TO-39	TO-52	TO-92	TO-220	Quad P-DIP	Quad C-DIP*	DICE†
-40V	8Ω	-0.5A	VP0104N2	VP0104N9	VP0104N3	VP0104N5	VP0104N6	VP0104N7	VP0104ND
-60V	8Ω	-0.5A	VP0106N2	VP0106N9	VP0106N3	VP0106N5	VP0106N6	VP0106N7	VP0106ND
-90V	8Ω	-0.5A	VP0109N2	VP0109N9	VP0109N3	VP0109N5	—	—	VP0109ND

* 14 pin side brazed ceramic DIP
† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

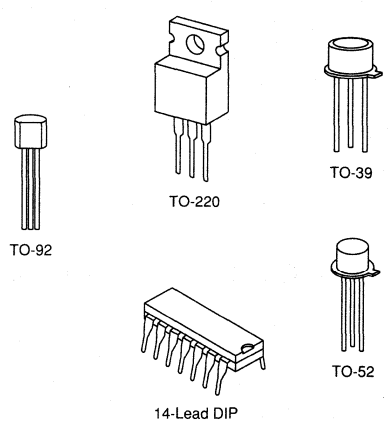
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Notes 1 and 2)



Note 1: See Package Outline section for discrete pinouts.
Note 2: See Array section for quad pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed) @ T_C = 25°C	Power Dissipation °C/W	θ_{ja} °C/W	θ_{jc}	I_{DR}*	I_{DRM}
TO-39	-0.45A	-1.0A	3.5W	125	35	-0.5A	-1.0A
TO-52	-0.25A	-1.0A	1.0W	170	125	-0.4A	-1.0A
TO-92	-0.25A	-0.8A	1.0W	170	125	-0.4A	-0.8A
TO-220	-1.0A	-1.0A	15.0W	70	8.3	-1.0A	-1.0A
Plastic Dip	Refer to Arrays & Special Functions Section.						
Ceramic Dip							

* I_D (continuous) is limited by max rated T_j.

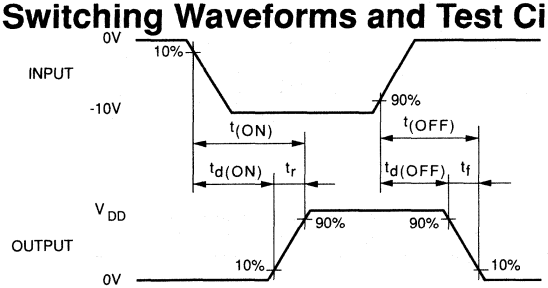
Electrical Characteristics (@ 25°C unless otherwise specified)

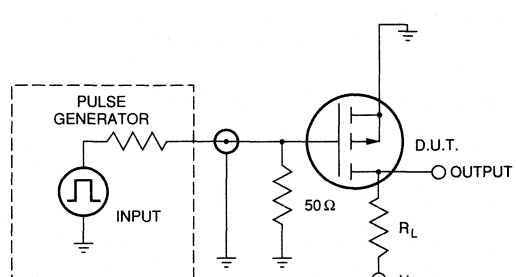
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP0109	-90			V	I_D = -1.0mA, V_{GS} = 0
		VP0106	-60				
		VP0104	-40				
$V_{GS(th)}$	Gate Threshold Voltage		-1.5		-3.5	V	V_{GS} = V_{DS}, I_D = -1.0mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			5.8	6.5	mV/°C	I_D = -1.0mA, V_{GS} = V_{DS}
I_{GSS}	Gate Body Leakage			-1.0	-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	µA	V_{GS} = 0, V_{DS} = Max Rating
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-0.15	-0.25		A	V_{GS} = -5V, V_{DS} = -25V
			-0.50	-1.0			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			11	15	Ω	V_{GS} = -5V, I_D = -0.1A
				5	8		V_{GS} = -10V, I_D = -0.5A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.55	1.0	%/°C	I_D = -0.5A, V_{GS} = -10V
G_{FS}	Forward Transconductance		150	200		m℧	V_{DS} = -25V, I_D = -0.5A
C_{ISS}	Input Capacitance			45	60	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			22	30		
C_{RSS}	Reverse Transfer Capacitance			3	8		
$t_{d(ON)}$	Turn-ON Delay Time			4	6	ns	V_{DD} = -25V, I_D = -1A, R_S = 50Ω
t_r	Rise Time			7	10		
$t_{d(OFF)}$	Turn-OFF Delay Time			3	5		
t_f	Fall Time			4	6		
V_{SD}	Diode Forward Voltage Drop			-1.2	-2.0	V	I_{SD} = -1.0A, V_{GS} = 0
t_{rr}	Reverse Recovery Time			400		ns	I_{SD} = -1.0A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

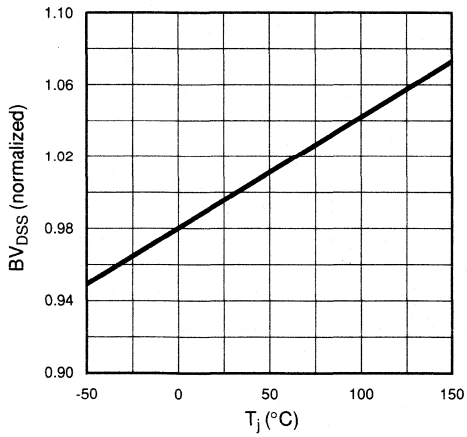
Switching Waveforms and Test Circuit



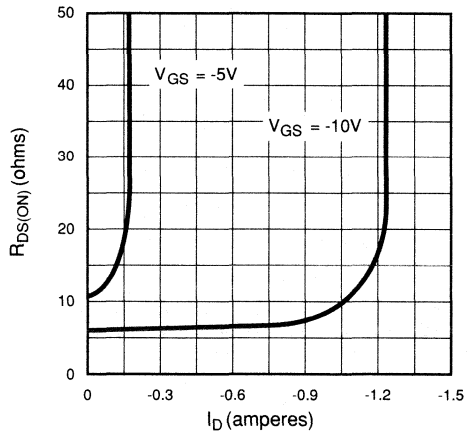


Typical Performance Curves

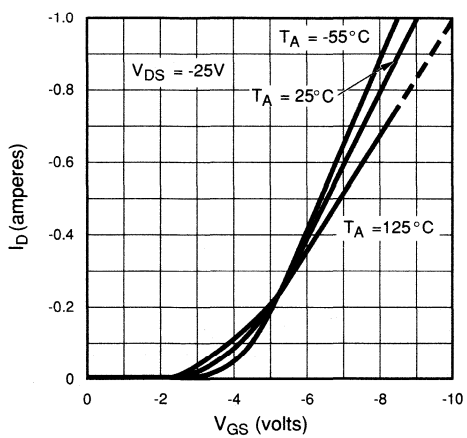
BV_{DSS} Variation with Temperature



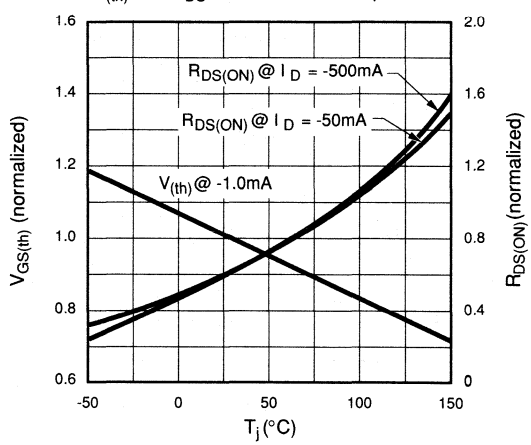
On-Resistance vs. Drain Current



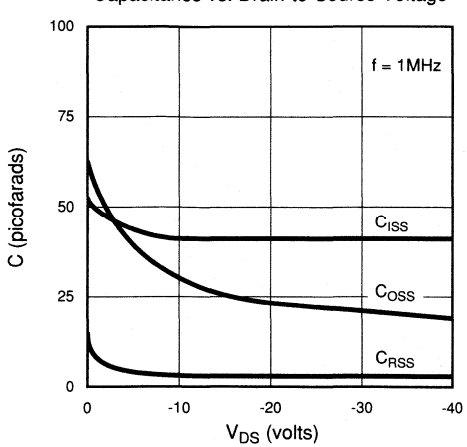
Transfer Characteristics



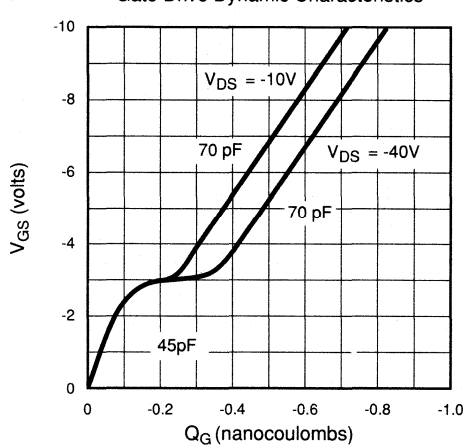
$V_{(th)}$ and R_{DS} Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



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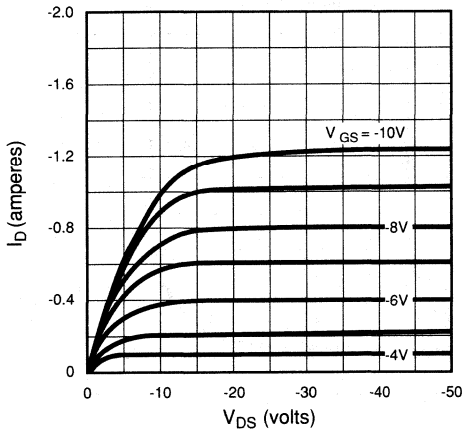
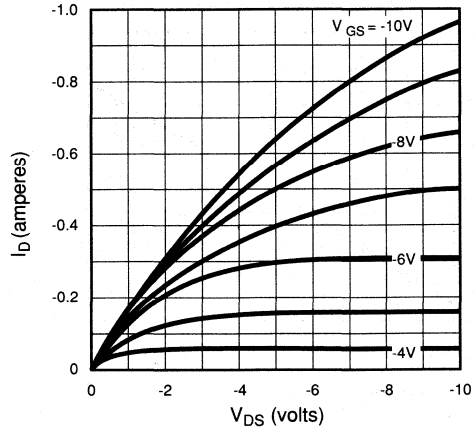
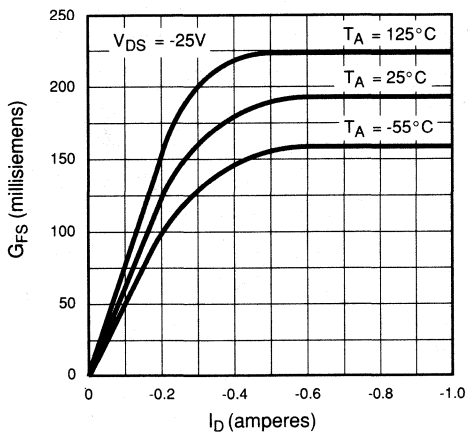
Output Characteristics



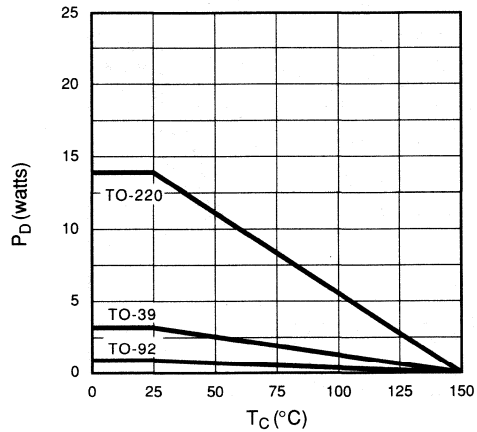
Saturation Characteristics



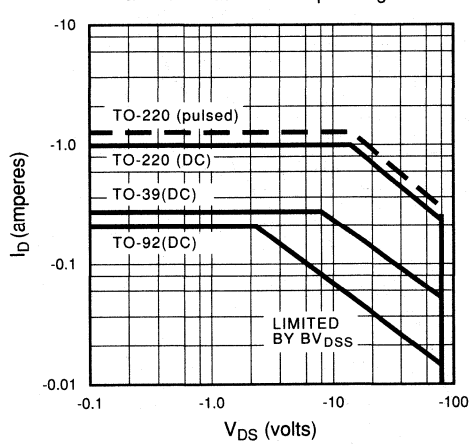
Transconductance vs. Drain Current



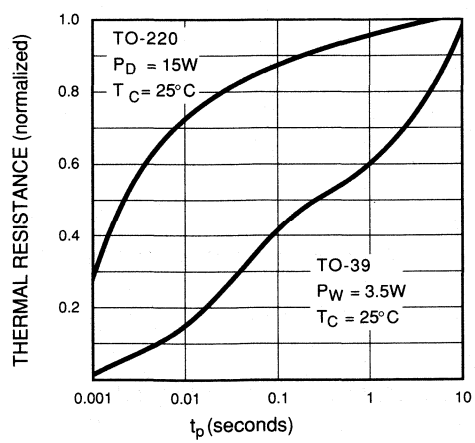
Power Dissipation vs. Case Temperature



Maximum Rated Safe Operating Area



Thermal Response Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package			
			TO-39	TO-92	TO-220	DICE†
-160V	25Ω	-100mA	VP0116N2	VP0116N3	VP0116N5	VP0116ND
-200V	25Ω	-100mA	VP0120N2	VP0120N3	VP0120N5	VP0120ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

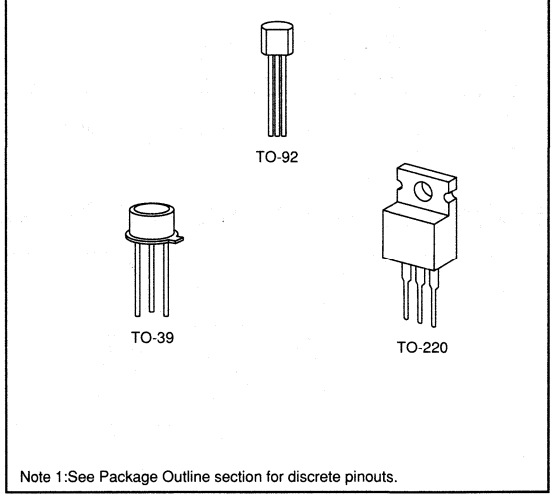
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



Note 1:See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	-0.2A	-0.65A	3.5W	125	35	-0.2A	-0.65A
TO-92	-0.1A	-0.35A	1.0W	170	125	-0.1A	-0.35A
TO-220	-0.425A	-1.0A	15.0W	70	8.3	-0.425A	-1.0A

* I_D (continuous) is limited by max rated T_j.

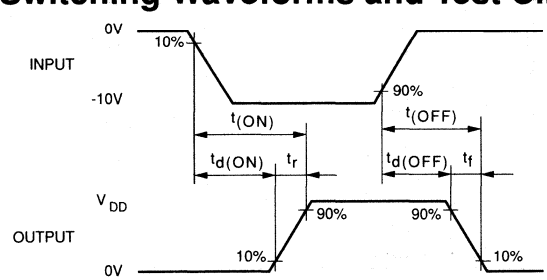
Electrical Characteristics (@ 25°C unless otherwise specified)

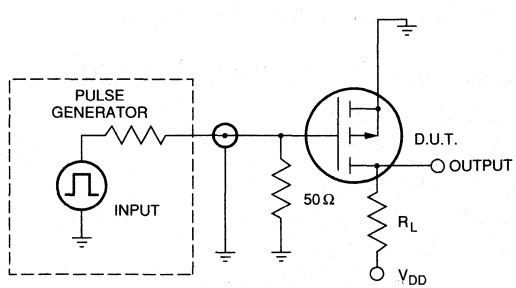
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP0120	-200			V	I_D = -1.0mA, V_{GS} = 0
		VP0116	-160				
$V_{GS(th)}$	Gate Threshold Voltage		-1.5		-3.5	V	V_{GS} = V_{DS}, I_D = -1.0mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			6.0		mV/°C	I_D = -1.0mA, V_{GS} = V_{DS}
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	µA	V_{GS} = 0, V_{DS} = Max Rating
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-100	-400		mA	V_{GS} = -5V, V_{DS} = -25V
			-350	-700			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			25	40	Ω	V_{GS} = -5V, I_D = -50mA
				15	25		V_{GS} = -10V, I_D = -100mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.6		%/°C	I_D = -100mA, V_{GS} = -10V
G_{FS}	Forward Transconductance		50	70		m℧	V_{DS} = -25V, I_D = -100mA
C_{ISS}	Input Capacitance			50	60	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			10	30		
C_{RSS}	Reverse Transfer Capacitance			5	10		
$t_{d(ON)}$	Turn-ON Delay Time			4	10	ns	V_{DD} = -25V, I_D = -100mA, R_S = 50Ω
t_r	Rise Time			4	10		
$t_{d(OFF)}$	Turn-OFF Delay Time			4	10		
t_f	Fall Time			4	10		
V_{SD}	Diode Forward Voltage Drop			-1.0		V	I_{SD} = -0.5A, V_{GS} = 0
t_{rr}	Reverse Recovery Time			500		ns	I_{SD} = -0.5A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

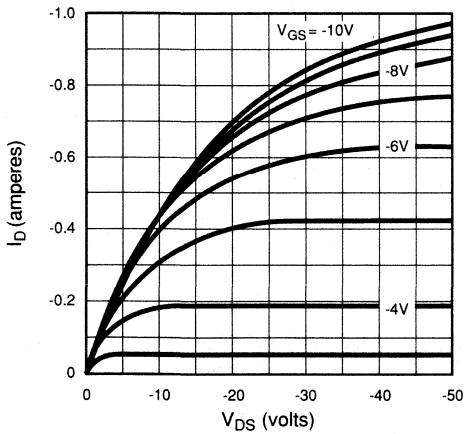
Switching Waveforms and Test Circuit



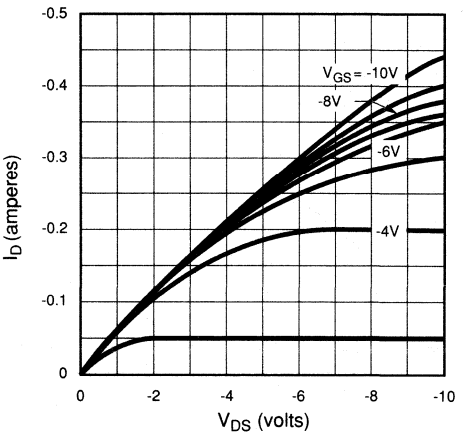


Typical Performance Curves

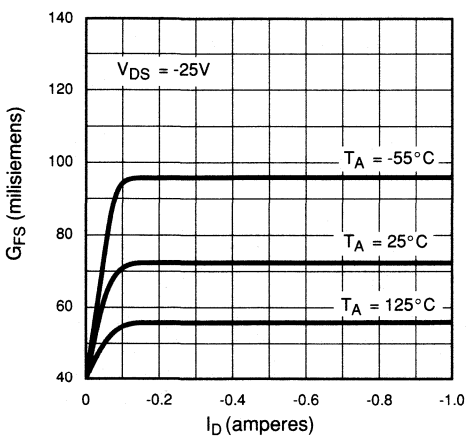
Output Characteristics



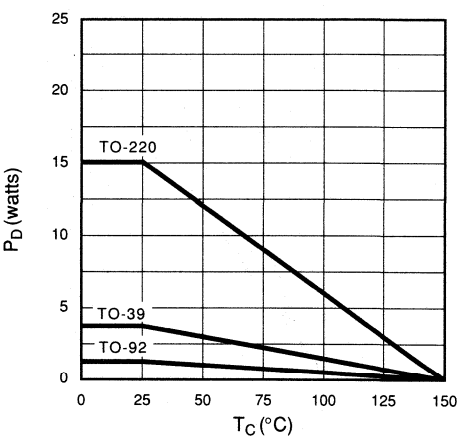
Saturation Characteristics



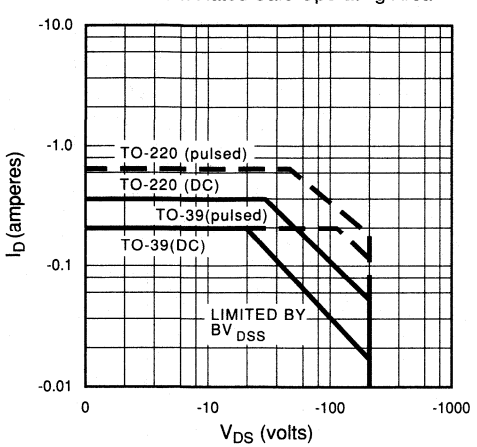
Transconductance vs. Drain Current



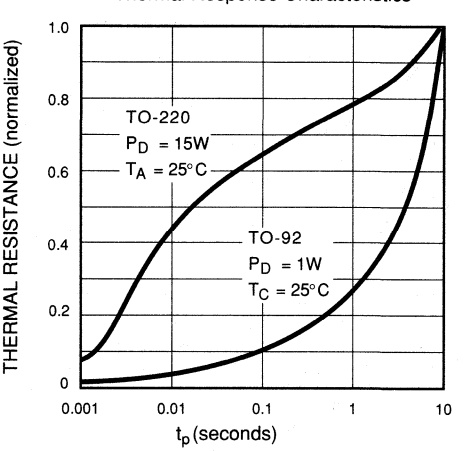
Power Dissipation vs. Case Temperature



Maximum Rated Safe Operating Area



Thermal Response Characteristics



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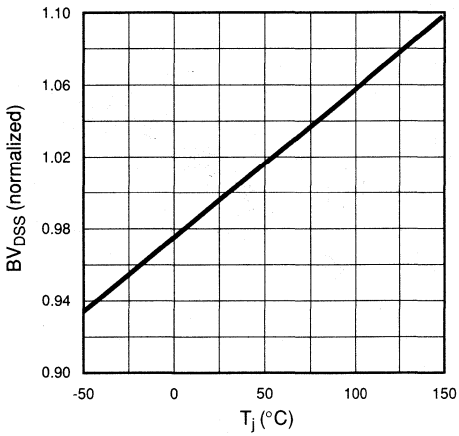
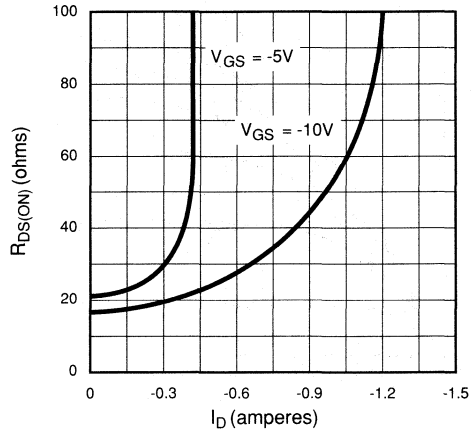
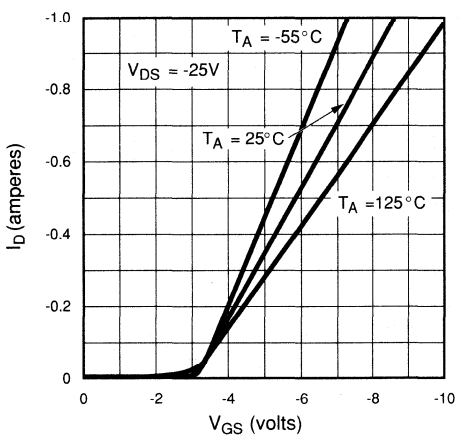
BV$_{DSS}$ Variation with Temperature



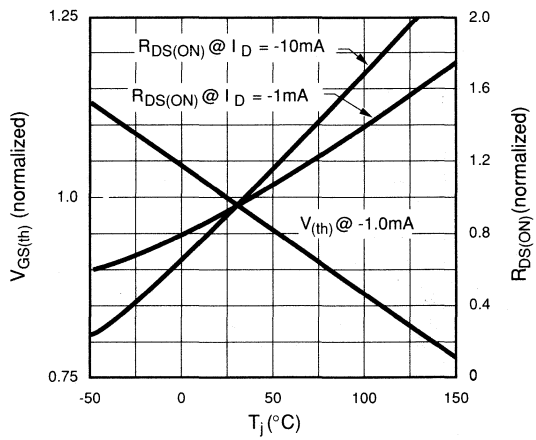
On-Resistance vs. Drain Current



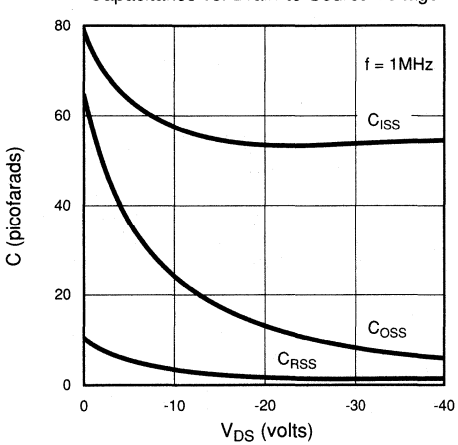
Transfer Characteristics



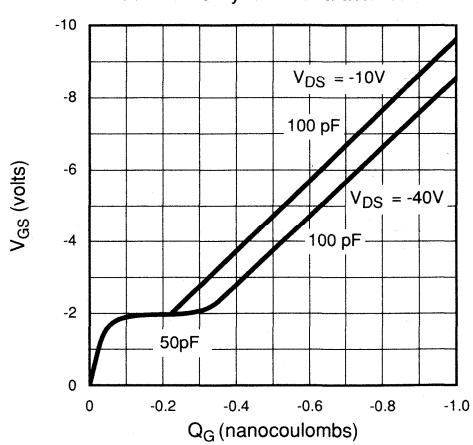
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



Supertex inc.

P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package			
			TO-3	TO-39	TO-220	DICE†
-350V	6Ω	-1.5A	VP0335N1	VP0335N2	VP0335N5	VP0335ND
-400V	6Ω	-1.5A	VP0340N1	VP0340N2	VP0340N5	VP0340ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

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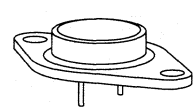
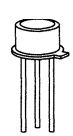
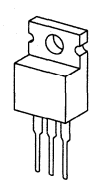
Package Options (Note 1)



TO-3



TO-39



TO-220

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-3	-2.7A	-5.0A	100W	1.25	30	-2.7A	-5.0A
TO-39	-0.7A	-5.0A	6W	20.8	125	-0.7A	-5.0A
TO-220	-1.6A	-5.0A	50W	2.5	40	-1.6A	-5.0A

* I_D (continuous) is limited by max rated T_j.

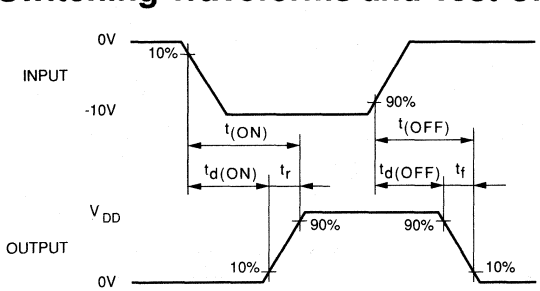
Electrical Characteristics (@ 25°C unless otherwise specified)

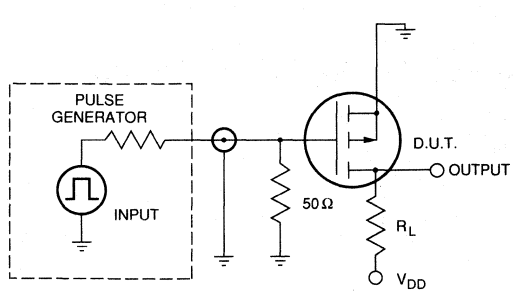
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP0340	-400			V	V_{GS} = 0, I_D = -10mA
		VP0335	-350				
$V_{GS(th)}$	Gate Threshold Voltage		-2.5		-4.5	V	V_{GS} = V_{DS}, I_D = -10mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			4.8	6.0	mV/°C	V_{GS} = V_{DS}, I_D = -10mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-200	µA	V_{GS} = 0, V_{DS} = Max Rating
					-2	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			-1.0		A	V_{GS} = -5V, V_{DS} = -25V
			-1.5	-3.5			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			5		Ω	V_{GS} = -5V, I_D = -0.25A
				4	6		V_{GS} = -10V, I_D = -0.5A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.7	1.2	%/°C	V_{GS} = -10V, I_D = -0.5A
G_{FS}	Forward Transconductance		0.5	0.6		℧	V_{DS} = -25V, I_D = -0.5A
C_{ISS}	Input Capacitance			550	700	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			90	120		
C_{RSS}	Reverse Transfer Capacitance			20	50		
$t_{d(ON)}$	Turn-ON Delay Time			25	40	ns	V_{DD} = -25V, I_D = -1A, R_S = 50Ω
t_r	Rise Time			25	40		
$t_{d(OFF)}$	Turn-OFF Delay Time			65	110		
t_f	Fall Time			20	40		
V_{SD}	Diode Forward Voltage Drop			-1	-1.3	V	V_{GS} = 0, I_{SD} = -0.5A
t_{rr}	Reverse Recovery Time			500		ns	V_{GS} = 0, I_{SD} = -0.5A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

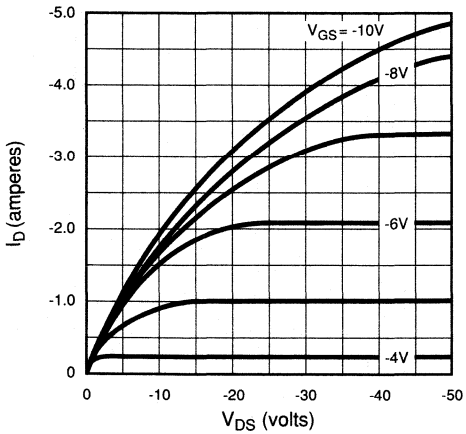
Switching Waveforms and Test Circuit



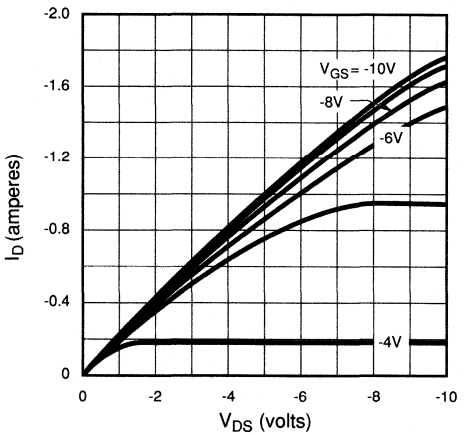


Typical Performance Curves

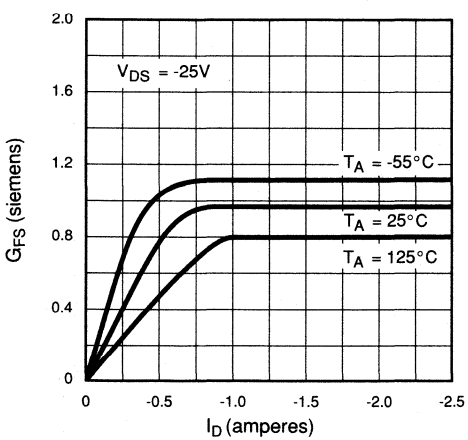
Output Characteristics



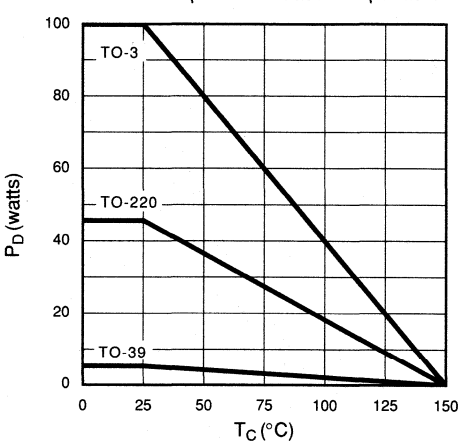
Saturation Characteristics



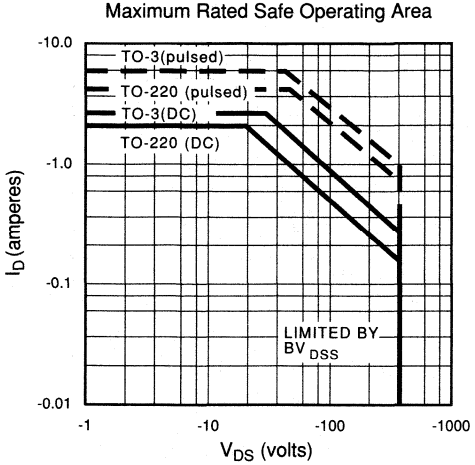
Transconductance vs. Drain Current



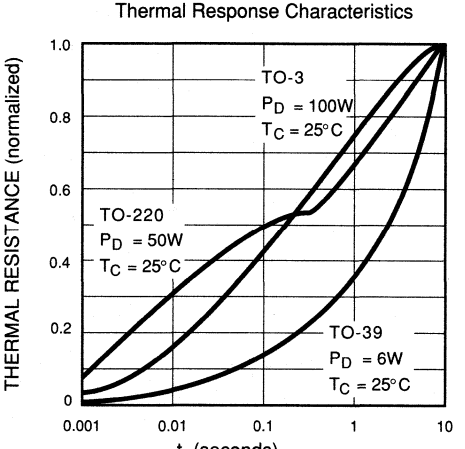
Power Dissipation vs. Case Temperature



Maximum Rated Safe Operating Area



Thermal Response Characteristics



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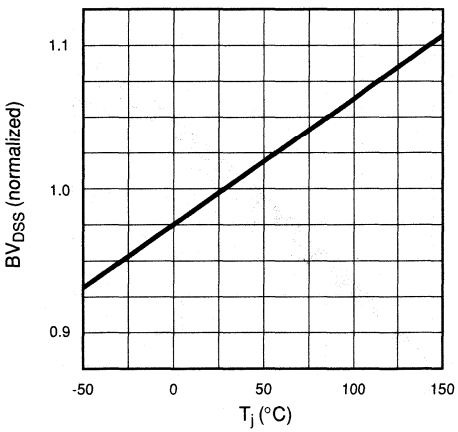
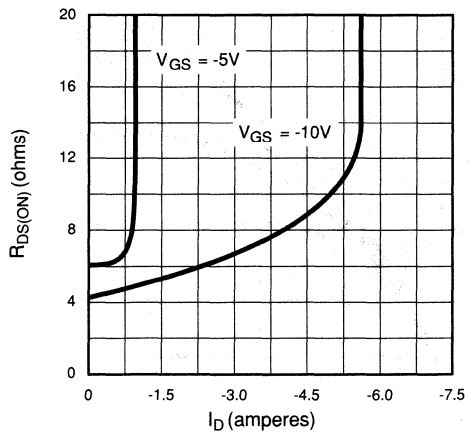
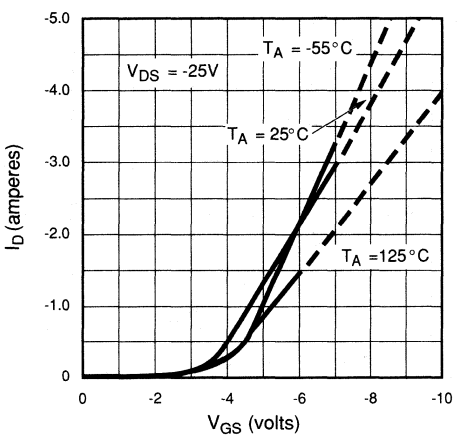
BV$_{DSS}$ Variation with Temperature



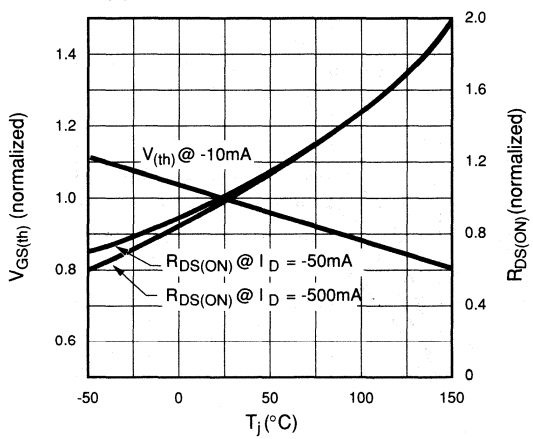
On-Resistance vs. Drain Current



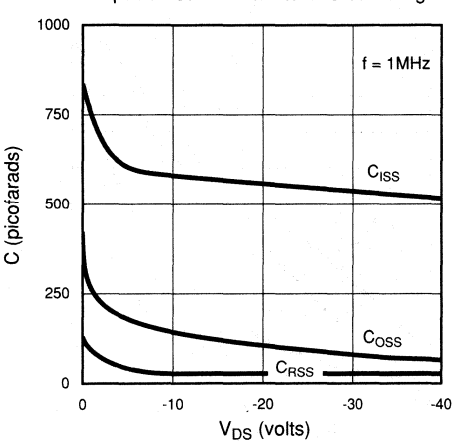
Transfer Characteristics



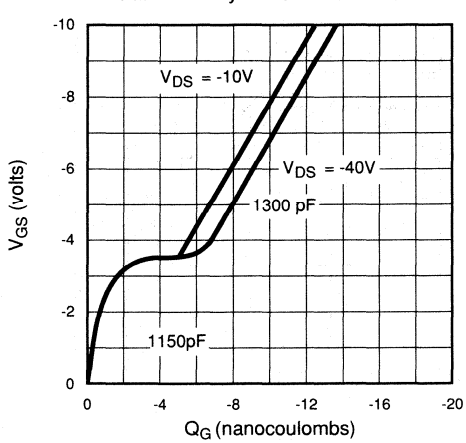
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package			
			TO-3	TO-39	TO-220	DICE†
-450V	7.5Ω	-1A	VP0345N1	VP0345N2	VP0345N5	VP0345ND
-500V	7.5Ω	-1A	VP0350N1	VP0350N2	VP0350N5	VP0350ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

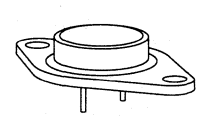
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

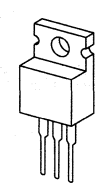
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

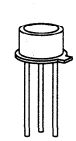
Package Options (Note 1)



TO-3



TO-220



TO-39

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-3	-1.5A	-3.0A	100W	1.25	30	-1.5A	-3.0A
TO-39	-0.4A	-3.0A	6W	20.8	125	-0.4A	-3.0A
TO-220	-1.0A	-3.0A	50W	2.5	40	-1.0A	-3.0A

* I_D (continuous) is limited by max rated T_j.

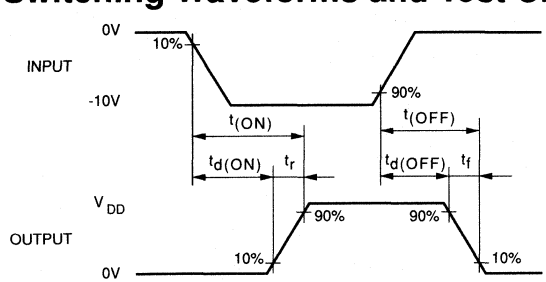
Electrical Characteristics (@ 25°C unless otherwise specified)

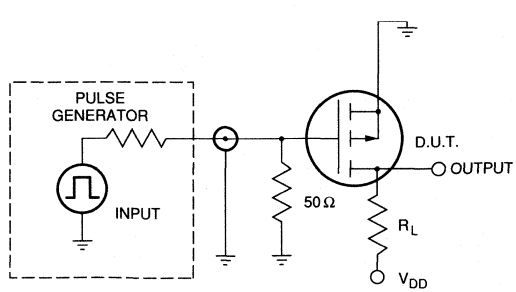
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP0350	-500			V	V_{GS}= 0, I_D =-10mA
		VP0345	-450				
$V_{GS(th)}$	Gate Threshold Voltage		-2.5		-4.5	V	V_{GS} = V_{DS}, I_D = -10mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			4.8	6.0	mV/°C	V_{GS} = V_{DS}, I_D = -10mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-200	µA	V_{GS} = 0, V_{DS} = Max Rating
					-2	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			-0.75		A	V_{GS} = -5V, V_{DS} = -25V
			-1.0				V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			6.0		Ω	V_{GS} = -5V, I_D = -0.25A
				5.5	7.5		V_{GS} = -10V, I_D = -0.25A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.7	1.2	%/°C	V_{GS} = -10V, I_D = -0.25A
G_{FS}	Forward Transconductance		0.25	0.5		℧	V_{DS} = -25V, I_D = -0.5A
C_{ISS}	Input Capacitance			720	800	pF	V_{GS} = 0, V_{DS} = -25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			110	130		
C_{RSS}	Reverse Transfer Capacitance			20	50		
$t_{d(ON)}$	Turn-ON Delay Time			11	30	ns	V_{DD} = -25V I_D = -0.5A R_S = 50Ω
t_r	Rise Time			11	30		
$t_{d(OFF)}$	Turn-OFF Delay Time			70	100		
t_f	Fall Time			22	30		
V_{SD}	Diode Forward Voltage Drop			-1.0	-1.3	V	V_{GS} = 0, I_{SD} = -0.25A
t_{rr}	Reverse Recovery Time			550		ns	V_{GS} = 0, I_{SD} = -0.25A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

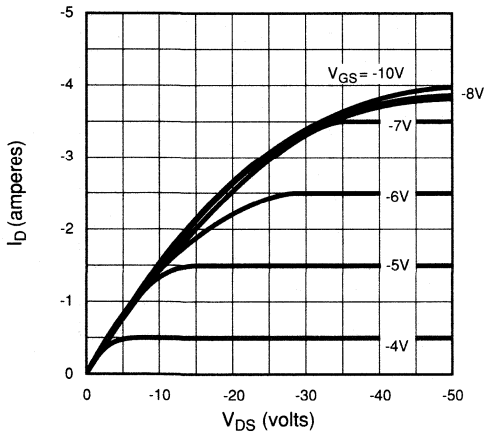
Switching Waveforms and Test Circuit



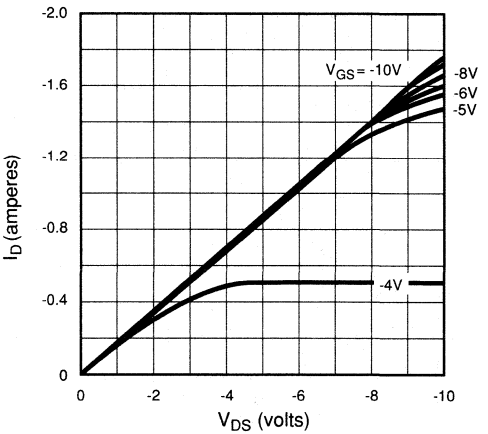


Typical Performance Curves

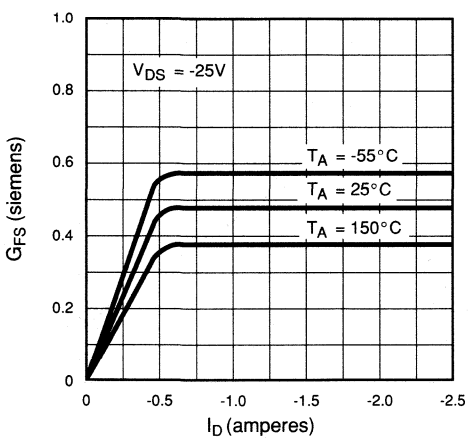
Output Characteristics



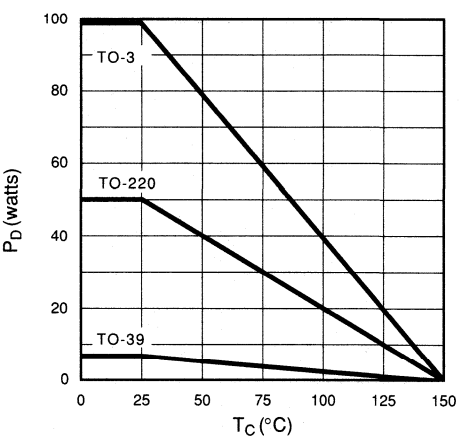
Saturation Characteristics



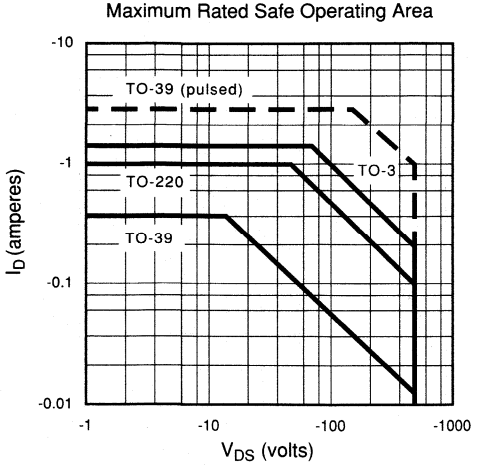
Transconductance vs. Drain Current



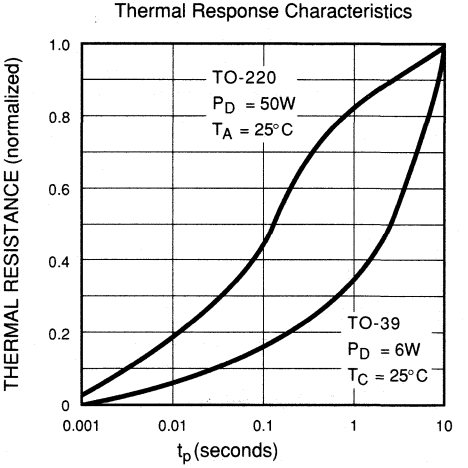
Power Dissipation vs. Case Temperature



Maximum Rated Safe Operating Area

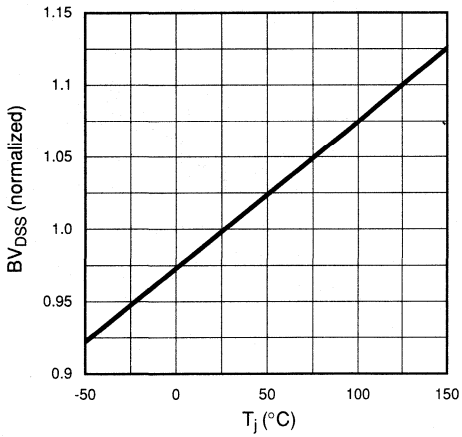


Thermal Response Characteristics

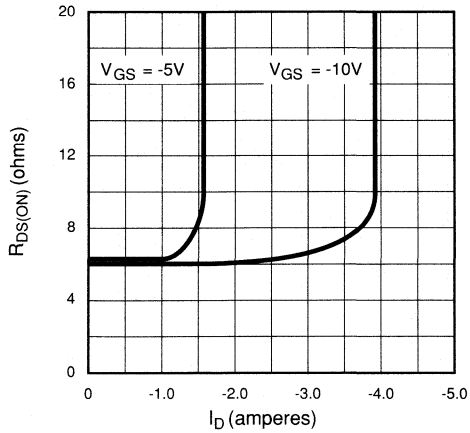


9

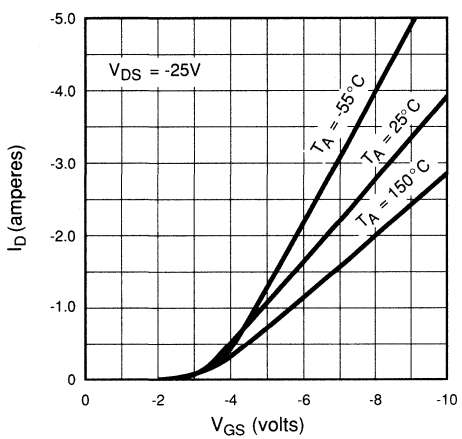
BV$_{DSS}$ Variation with Temperature



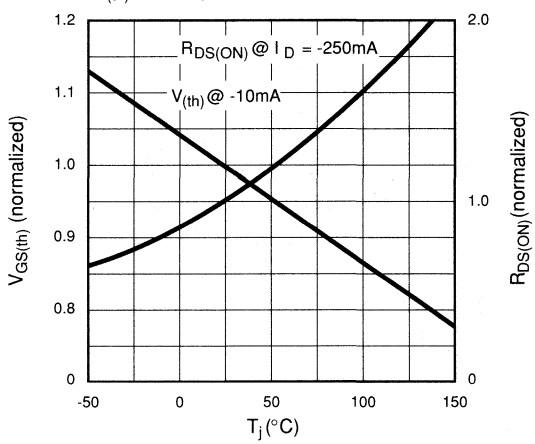
On-Resistance vs. Drain Current



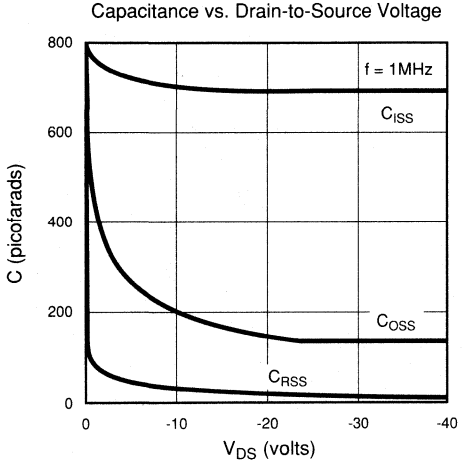
Transfer Characteristics



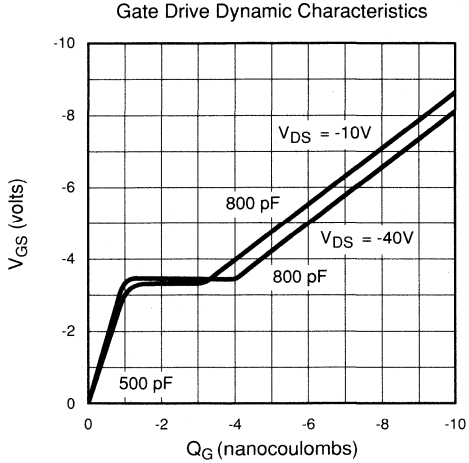
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
			TO-39	TO-92
-30V	2.5Ω	-1.5A	VP0300B	VP0300L

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	±40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

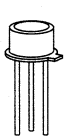
Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

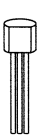
Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options

(Note 1)



TO-39



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation	θ_{ja} °C/W	θ_{jc} °C/W
TO-39	-1.25A	-3.0A	6.25W	170	20
TO-92	-0.32A	-0.87A	0.4W	312.5	41

* I_D (continuous) is limited by max rated T_j.

Electrical Characteristics (@ 25°C unless otherwise specified)

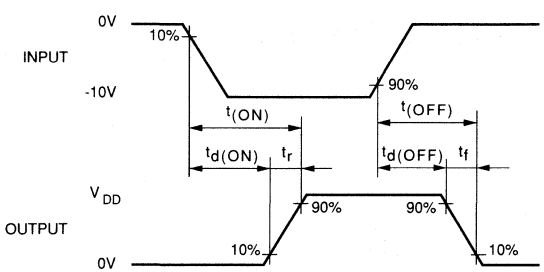
(Notes 1 and 2)

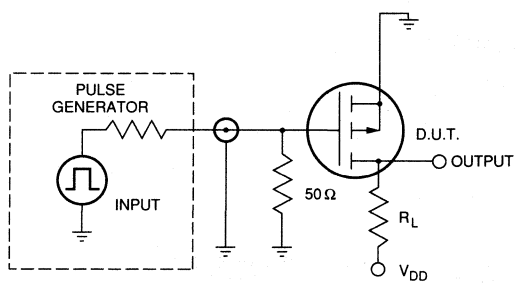
Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	-30			V	V_{GS}= 0, I_D =-10µA
$V_{GS(th)}$	Gate Threshold Voltage	-1.0	-1.8	-4.5	V	V_{GS} = V_{DS}, I_D = -1mA
I_{GSS}	Gate Body Leakage			-100	nA	V_{GS} = ±30V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			-10	µA	V_{GS} = 0, V_{DS} = -25
				-500		V_{GS} = 0, V_{DS} = -25V T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	-1.5	-1.7		A	V_{GS} = -12V, V_{DS} ≥ $2V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-SourceON-State Resistance			2.5	Ω	V_{GS} = -12V, I_D = -1A
G_{FS}	Forward Transconductance	200			m℧	V_{DS} ≥ $2V_{DS(ON)}$, I_D = -0.5A
C_{ISS}	Input Capacitance			150	pF	V_{GS} = 0V, V_{DS} = -15V f = 1MHz
C_{OSS}	Common Source Output Capacitance			120		
C_{RSS}	Reverse Transfer Capacitance			60		
$t_{(ON)}$	Turn-ON Time			30	ns	V_{DD} = -25V, I_D = -1A R_S = 50Ω
$t_{(OFF)}$	Turn-OFF Time			30		
V_{SD}	Diode Forward Voltage Drop		-1.2		V	V_{GS} = 0, I_{SD} = -1.5A

Notes

1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-92	DICE†
-350V	75Ω	-200mA	VP0535N2	VP0535N3	VP0535ND
-400V	75Ω	-200mA	VP0540N2	VP0540N3	VP0540ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

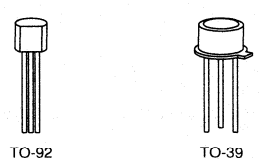
Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

9

Package Options (Note 1)



TO-92 TO-39

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-39	-0.2A	-0.5A	3.5W	35	125	-0.2A	-0.5A
TO-92	-0.1A	-0.5A	1.0W	125	170	-0.1A	-0.5A

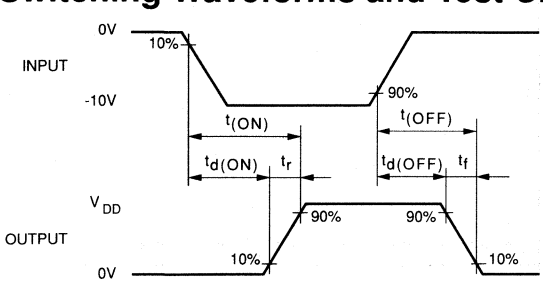
* I_D (continuous) is limited by max rated T_j.

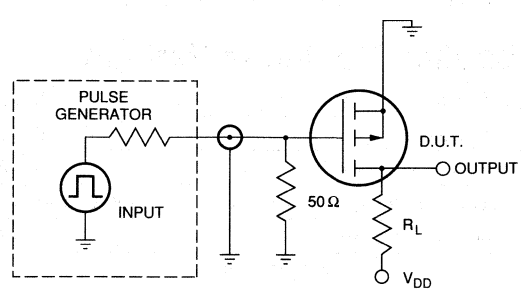
Electrical Characteristics

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP0540	-400			V	V_{GS}= 0, I_D =-1mA
		VP0535	-350				
$V_{GS(th)}$	Gate Threshold Voltage		-2.5		-4.5	V	V_{GS} = V_{DS}, I_D = -1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			3.5	6.0	mV/°C	V_{GS} = V_{DS}, I_D = -1mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	µA	V_{GS} = 0, V_{DS} = Max Rating
					-500		V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			-80		A	V_{GS} = -5V, V_{DS} = -25V
			-200	-350			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			60		Ω	V_{GS} = -5V, I_D = -10mA
				45	75		V_{GS} = -10V, I_D = -50mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.8	1.5	%/°C	V_{GS} = -10V, I_D = -50mA
G_{FS}	Forward Transconductance		50	70		m℧	V_{DS} = -25V, I_D = -50mA
C_{ISS}	Input Capacitance			40	60	pF	V_{GS} = 0, V_{DS} = -25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			11	20		
C_{RSS}	Reverse Transfer Capacitance			3	5		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = -25V I_D = -50mA R_S = 50Ω
t_r	Rise Time				15		
$t_{d(OFF)}$	Turn-OFF Delay Time				15		
t_f	Fall Time				10		
V_{SD}	Diode Forward Voltage Drop			-0.8	-1.5	V	V_{GS} = 0, I_{SD} = -0.1A
t_{rr}	Reverse Recovery Time			200		ns	V_{GS} = 0, I_{SD} = -0.1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

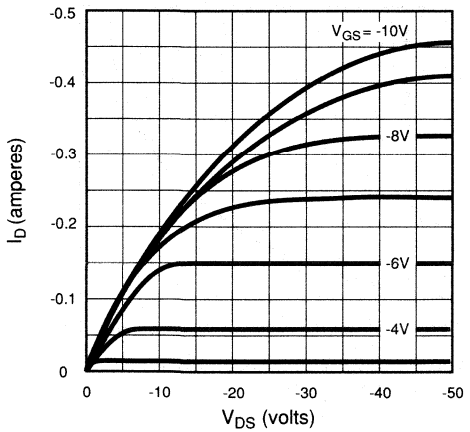
Switching Waveforms and Test Circuit



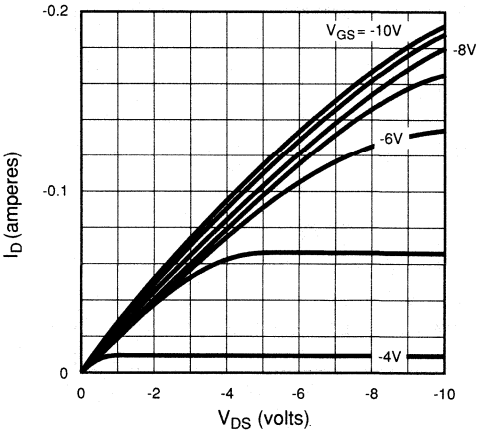


Typical Performance Curves

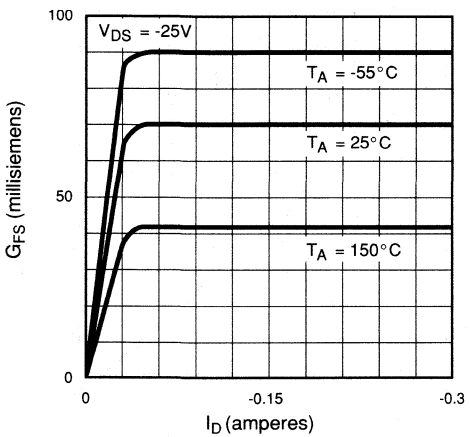
Output Characteristics



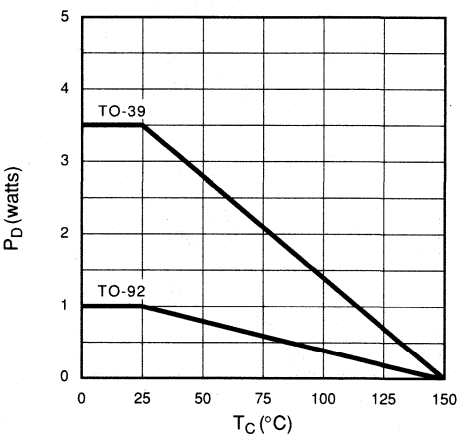
Saturation Characteristics



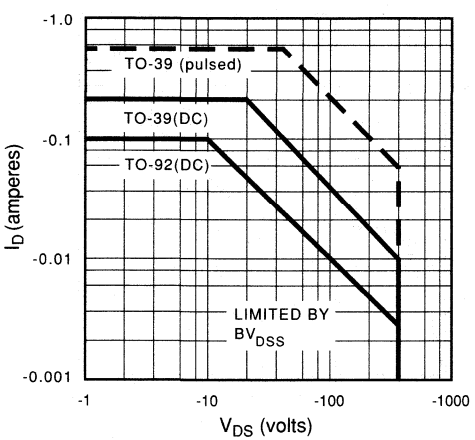
Transconductance vs. Drain Current



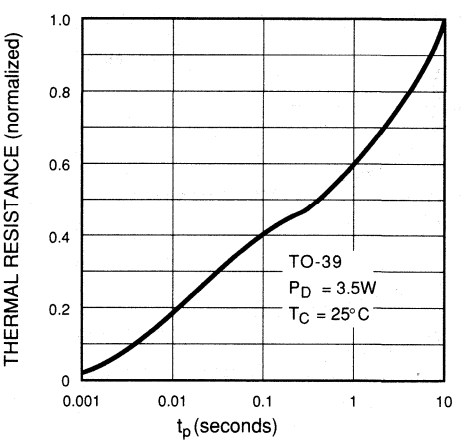
Power Dissipation vs. Case Temperature



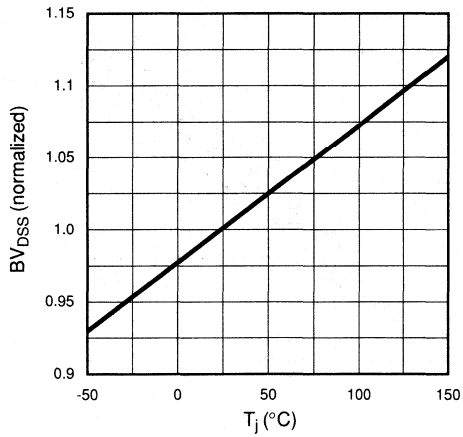
Maximum Rated Safe Operating Area



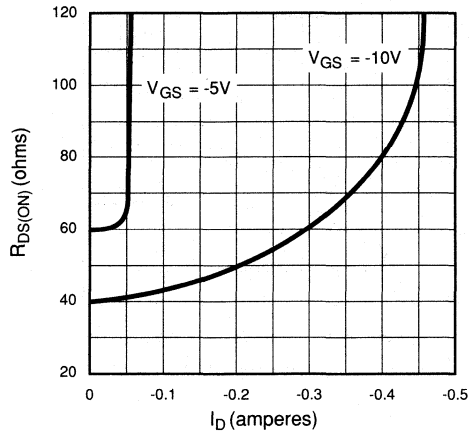
Thermal Response Characteristics



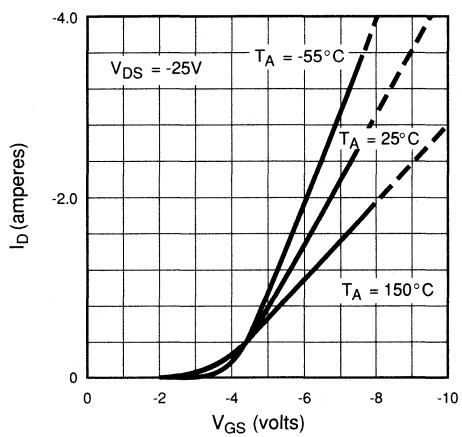
BV$_{DSS}$ Variation with Temperature



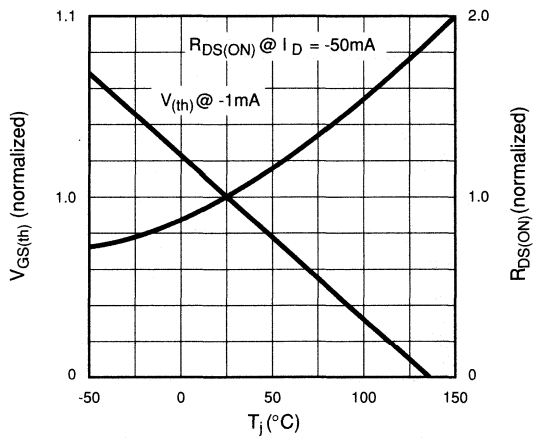
On-Resistance vs. Drain Current



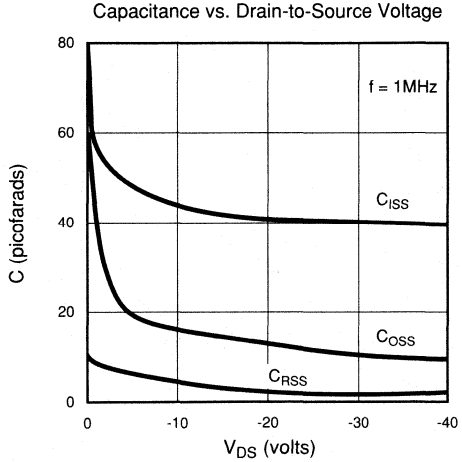
Transfer Characteristics



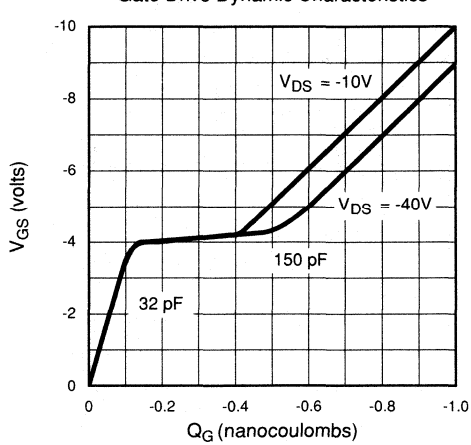
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-92	DICE†
-450V	125Ω	-100mA	VP0545N2	VP0545N3	VP0545ND
-500V	125Ω	-100mA	VP0550N2	VP0550N3	VP0550ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

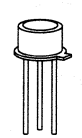
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

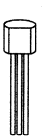
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note1)



TO-39



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-39	-125mA	-0.25A	3.5W	35	125	-125mA	-0.25A
TO-92	-70mA	-0.25A	1W	125	170	-70mA	-0.25A

* I_D (continuous) is limited by max rated T_j.

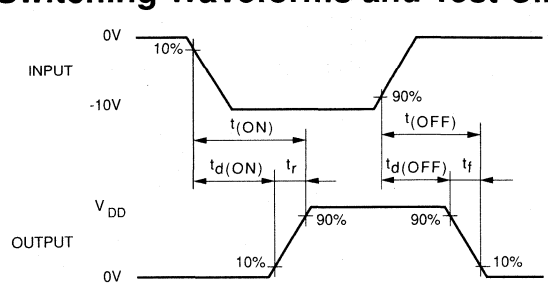
Electrical Characteristics (@ 25°C unless otherwise specified)

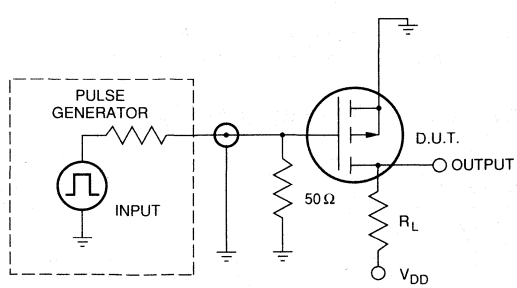
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP0550	-500			V	V_{GS} = 0, I_D = -1mA
		VP0545	-450				
$V_{GS(th)}$	Gate Threshold Voltage		-2.5		-4.5	V	V_{GS} = V_{DS}, I_D = -1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			3.5	6	mV/°C	V_{GS} = V_{DS}, I_D = -1mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	μA	V_{GS} = 0, V_{DS} = Max Rating
					-1000		V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			-90		mA	V_{GS} = -5V, V_{DS} = -25V
			-100	-240			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			85		Ω	V_{GS} = -5V, I_D = -5mA
				75	125		V_{GS} = -10V, I_D = -10mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.85		%/°C	V_{GS} = -10V, I_D = -10mA
G_{FS}	Forward Transconductance		25	40		m℧	V_{DS} = -25V, I_D = -10mA
C_{ISS}	Input Capacitance			40	60	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			10	20		
C_{RSS}	Reverse Transfer Capacitance			3	10		
$t_{d(ON)}$	Turn-ON Delay Time			5	10	ns	V_{DD} = -25V, I_D = -100mA, R_S = 50Ω
t_r	Rise Time			8	15		
$t_{d(OFF)}$	Turn-OFF Delay Time			8	15		
t_f	Fall Time			5	10		
V_{SD}	Diode Forward Voltage Drop			-0.8	-1.5	V	V_{GS} = 0, I_{SD} = -0.1A
t_{rr}	Reverse Recovery Time			200		ns	V_{GS} = 0, I_{SD} = -0.1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

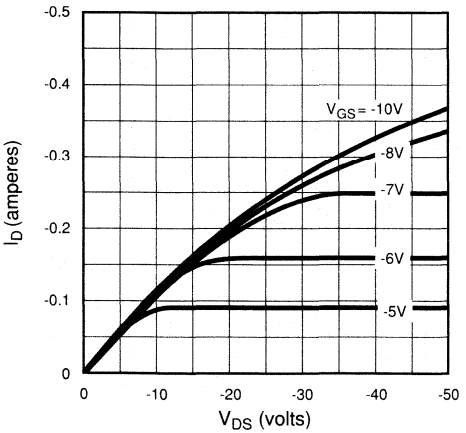
Switching Waveforms and Test Circuit



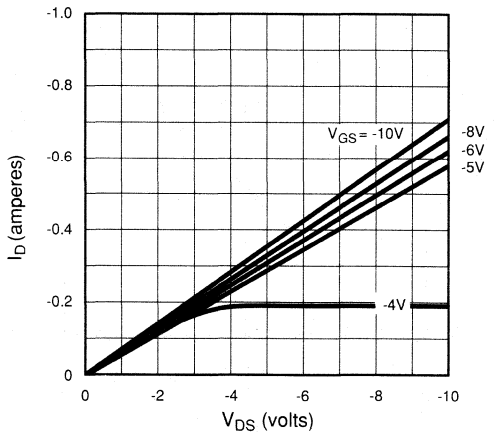


Typical Performance Curves

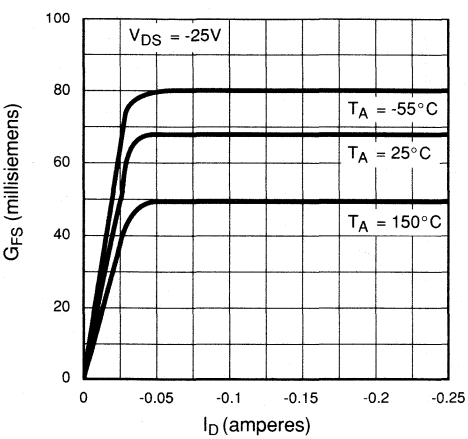
Output Characteristics



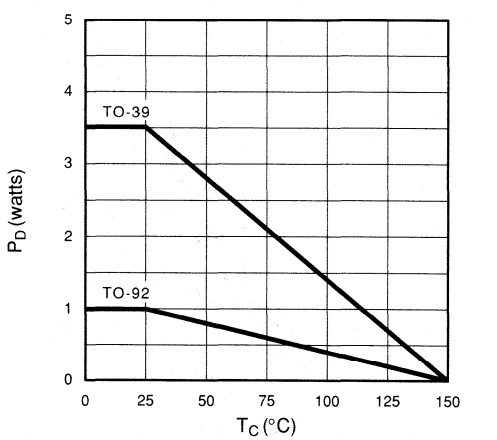
Saturation Characteristics



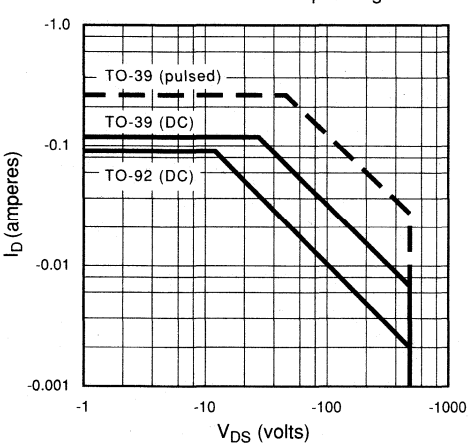
Transconductance vs. Drain Current



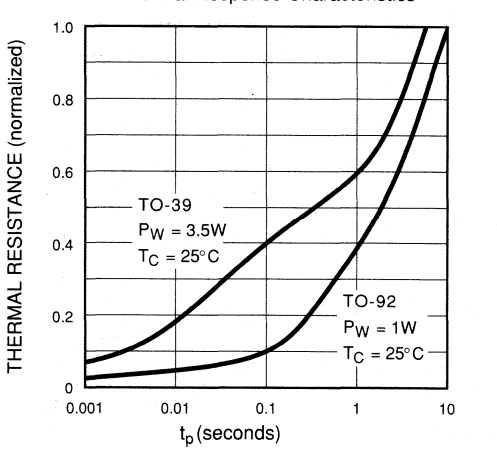
Power Dissipation vs. Case Temperature



Maximum Rated Safe Operating Area



Thermal Response Characteristics



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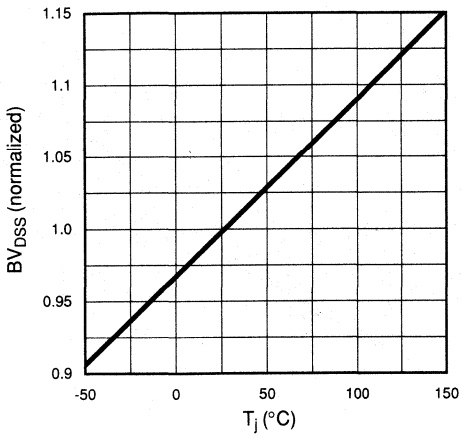
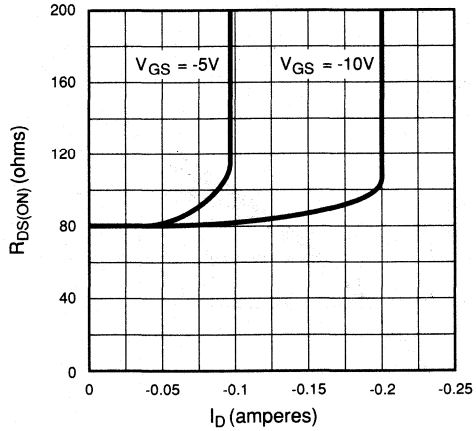
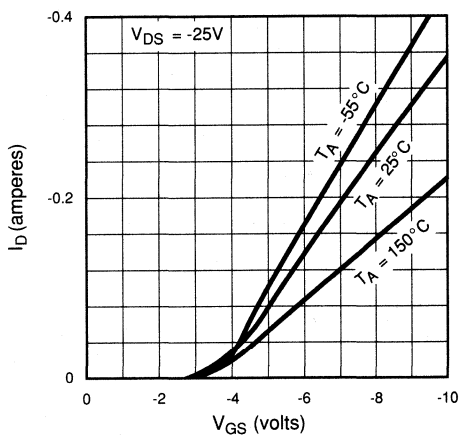
BV$_{DSS}$ Variation with Temperature



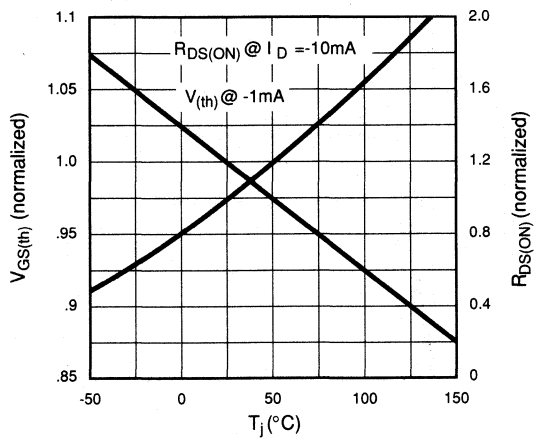
On-Resistance vs. Drain Current



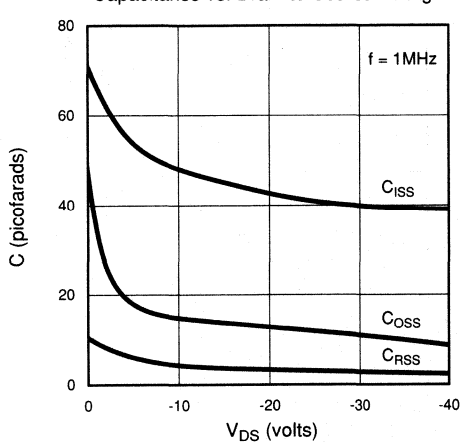
Transfer Characteristics



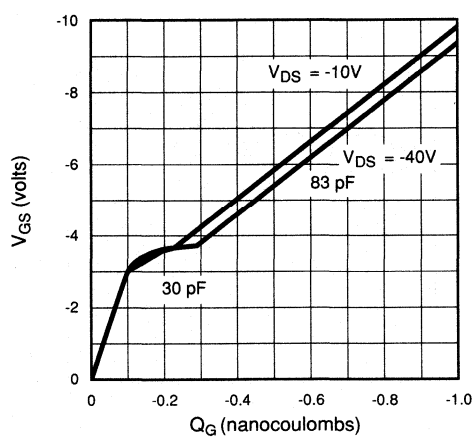
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package			
			TO-39	TO-92	TO-220	DICE†
-350V	25Ω	-0.4A	VP0635N2	VP0635N3	VP0635N5	VP0635ND
-400V	25Ω	-0.4A	VP0640N2	VP0640N3	VP0640N5	VP0640ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

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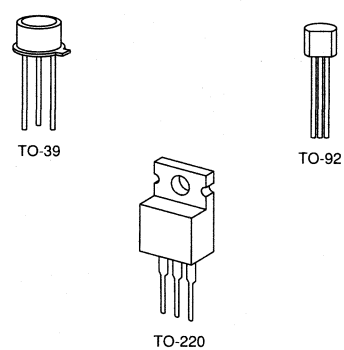
9

Package Options (Note1)



Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-92	-0.30A	-0.6A	1W	125	170	-0.30A	-0.6A
TO-39	-0.40A	-0.75A	6W	21	125	-0.40A	-0.75A
TO-220	-0.40A	-0.75A	28W	2.7	70	-0.40A	-0.75A

* I_D (continuous) is limited by max rated T_j.

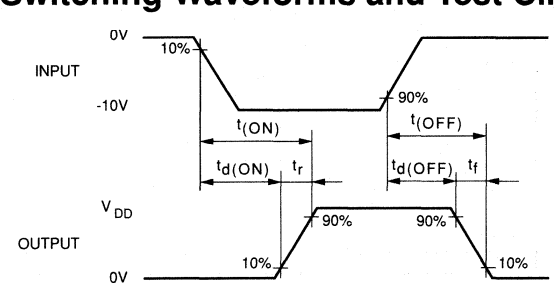
Electrical Characteristics (@ 25°C unless otherwise specified)

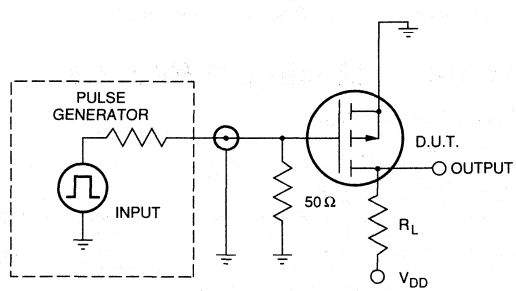
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP0640	-400			V	V_{GS} = 0, I_D = -2mA
		VP0635	-350				
$V_{GS(th)}$	Gate Threshold Voltage		-2		-4	V	V_{GS} = V_{DS}, I_D = -2mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				4.8	mV/°C	V_{GS} = V_{DS}, I_D = -2mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	µA	V_{GS} = 0, V_{DS} = Max Rating
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			0.3		A	V_{GS} = -5V, V_{DS} = -25V
			-0.4	1.1			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			20		Ω	V_{GS} = -5V, I_D = -100mA
				19	25		V_{GS} = -10V, I_D = -100mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				0.75	%/°C	V_{GS} = -10V, I_D = -100mA
G_{FS}	Forward Transconductance		100			m℧	V_{DS} = -25V, I_D = -100mA
C_{ISS}	Input Capacitance			105	130	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			30	75		
C_{RSS}	Reverse Transfer Capacitance			10	20		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = -25V, I_D = -100mA, R_S = 50Ω
t_r	Rise Time				10		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				10		
V_{SD}	Diode Forward Voltage Drop				-1.8	V	V_{GS} = 0, I_{SD} = -100mA
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = -100mA

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

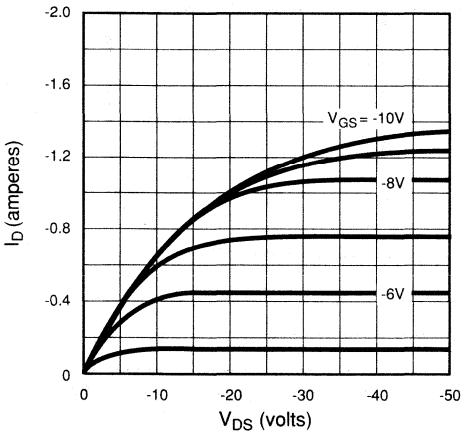
Switching Waveforms and Test Circuit



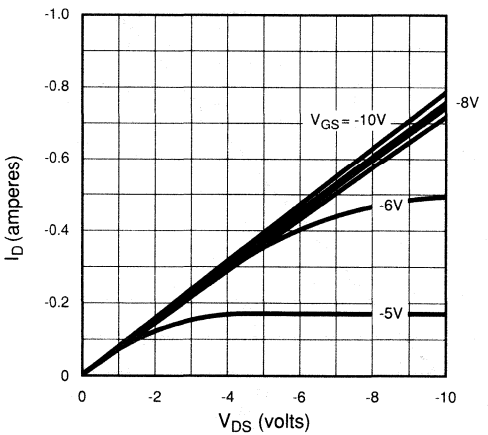


Typical Performance Curves

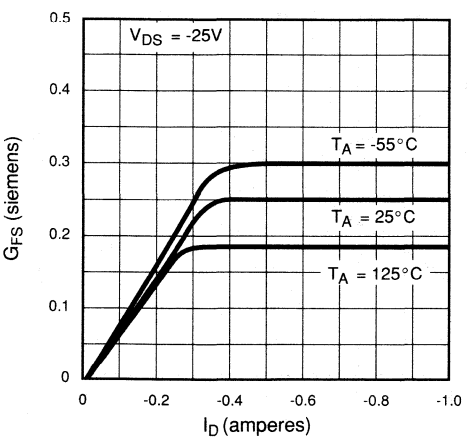
Output Characteristics



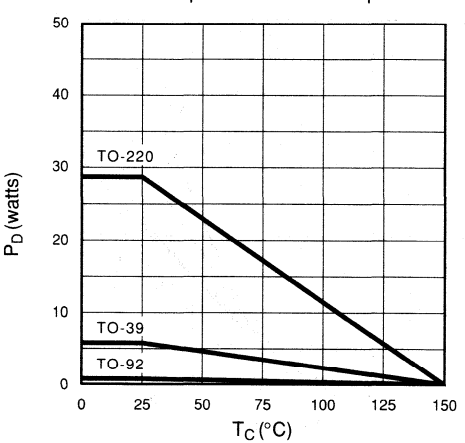
Saturation Characteristics



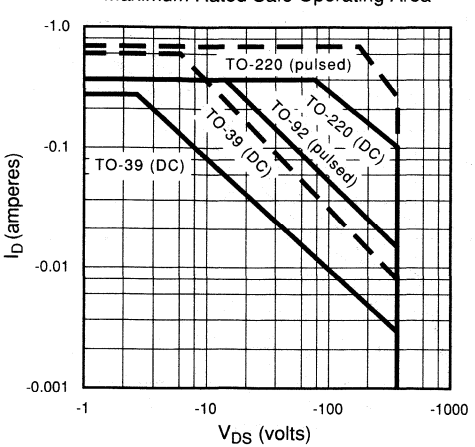
Transconductance vs. Drain Current



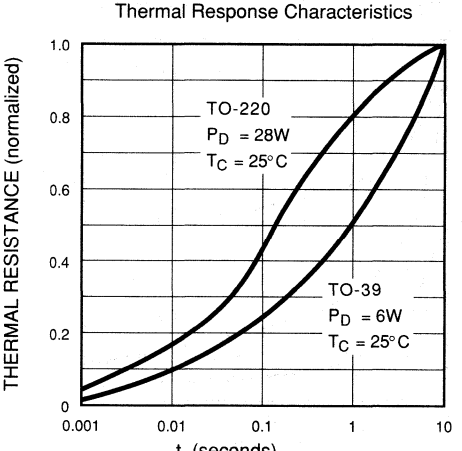
Power Dissipation vs. Case Temperature



Maximum Rated Safe Operating Area



Thermal Response Characteristics



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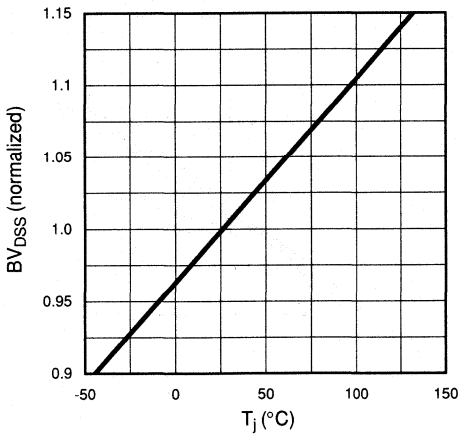
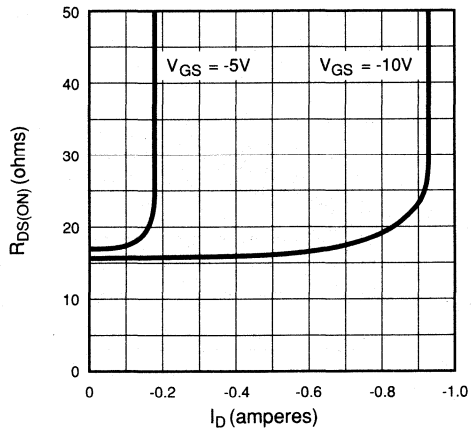
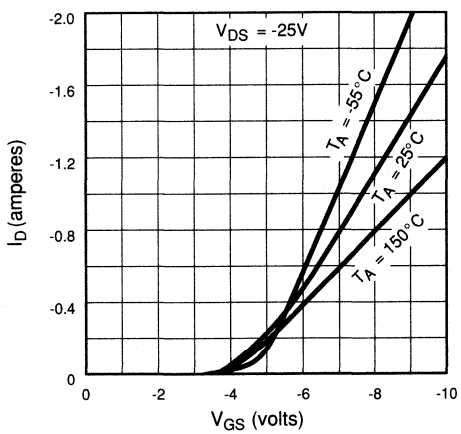
BV$_{DSS}$ Variation with Temperature



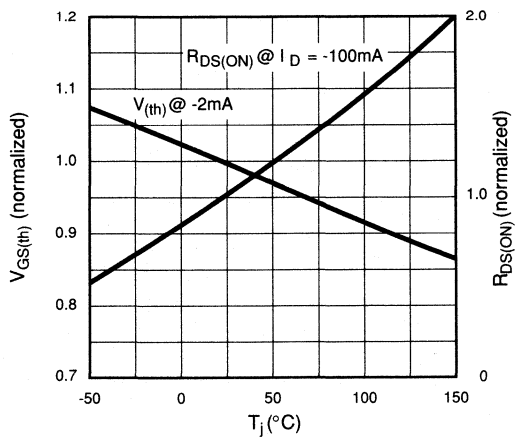
On-Resistance vs. Drain Current



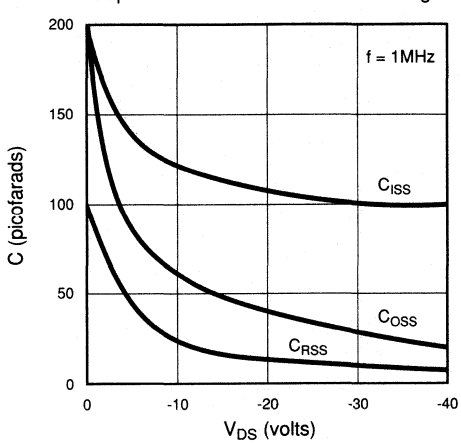
Transfer Characteristics



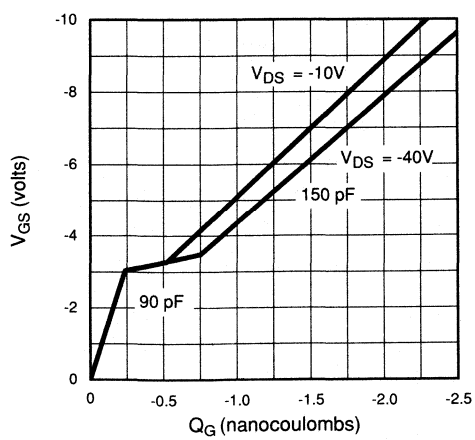
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package			
			TO-39	TO-92	TO-220	DICE†
-450V	30Ω	-0.2A	VP0645N2	VP0645N3	VP0645N5	VP0645ND
-500V	30Ω	-0.2A	VP0650N2	VP0650N3	VP0650N5	VP0650ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

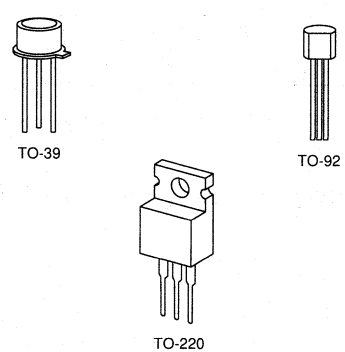
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{jc} °C/W	θ_{ja} °C/W	I_{DR}*	I_{DRM}
TO-92	-0.1A	-0.3A	1W	125	170	-0.1A	-0.3A
TO-39	-0.25A	-0.5A	6W	21	125	-0.25A	-0.5A
TO-220	-0.25A	-0.5A	45W	2.7	70	-0.25A	-0.5A

* I_D (continuous) is limited by max rated T_j.

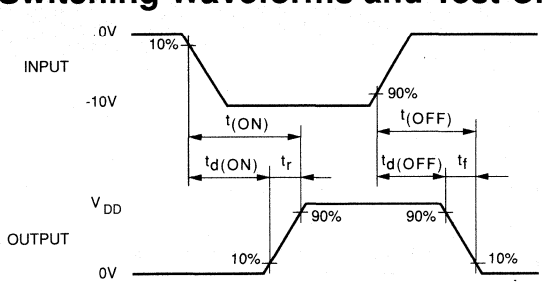
Electrical Characteristics (@ 25°C unless otherwise specified)

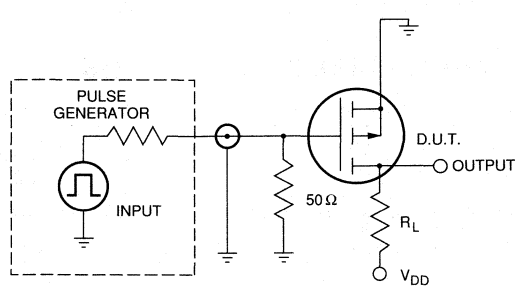
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP0650	-500			V	V_{GS} = 0, I_D = -2mA
		VP0645	-450				
$V_{GS(th)}$	Gate Threshold Voltage		-2		-4	V	V_{GS} = V_{DS}, I_D = -2mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				-4.8	mV/°C	V_{GS} = V_{DS}, I_D = -2mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	µA	V_{GS} = 0, V_{DS} = Max Rating
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current			-200		mA	V_{GS} = -5V, V_{DS} = -25V
			-200	-600			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			30		Ω	V_{GS} = -5V, I_D = -100mA
				22	30		V_{GS} = -10V, I_D = -100mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature				0.75	%/°C	V_{GS} = -10V, I_D = -100mA
G_{FS}	Forward Transconductance		50			m℧	V_{DS} = -25V, I_D = -100mA
C_{ISS}	Input Capacitance			95	130	pF	V_{GS} = 0, V_{DS} =- 25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			50	75		
C_{RSS}	Reverse Transfer Capacitance				20		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = -25V, I_D = -100mA, R_S = 50Ω
t_r	Rise Time				10		
$t_{d(OFF)}$	Turn-OFF Delay Time				20		
t_f	Fall Time				15		
V_{SD}	Diode Forward Voltage Drop				-1.8	V	V_{GS} = 0, I_{SD} = -50mA
t_{rr}	Reverse Recovery Time			300		ns	V_{GS} = 0, I_{SD} = -50mA

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

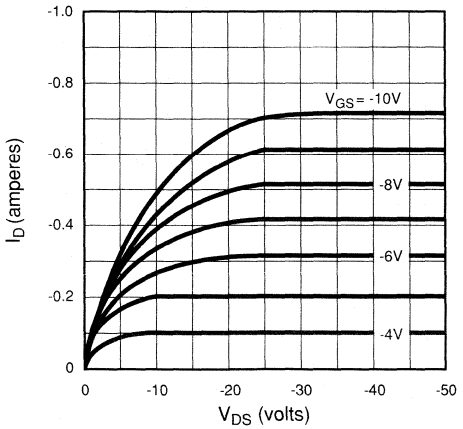
Switching Waveforms and Test Circuit



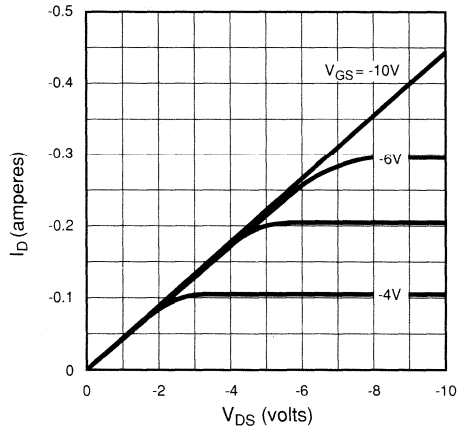


Typical Performance Curves

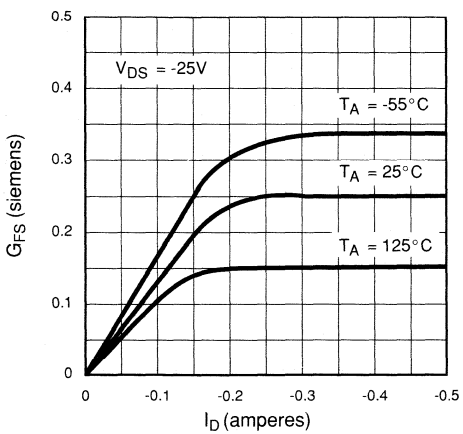
Output Characteristics



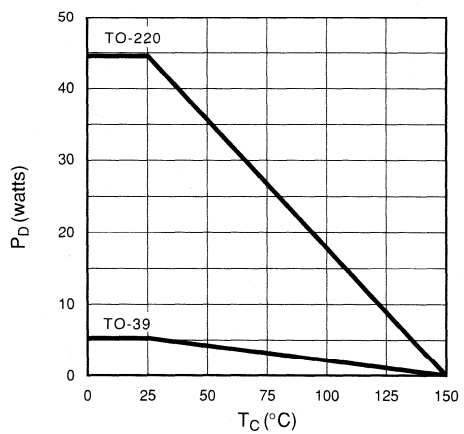
Saturation Characteristics



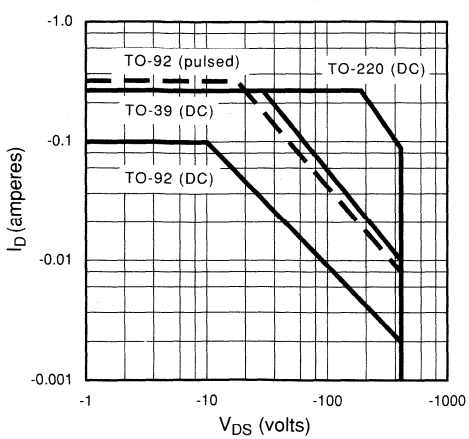
Transconductance vs. Drain Current



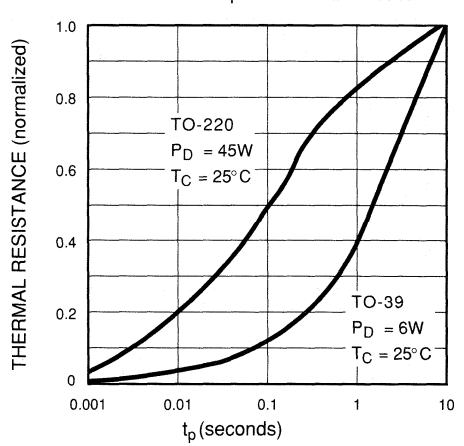
Power Dissipation vs. Case Temperature



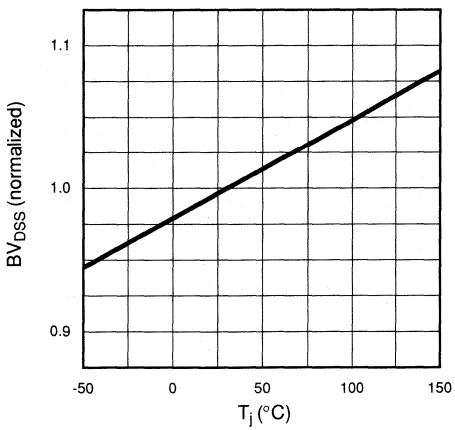
Maximum Rated Safe Operating Area



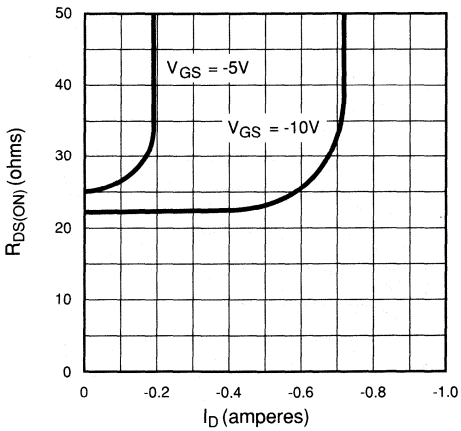
Thermal Response Characteristics



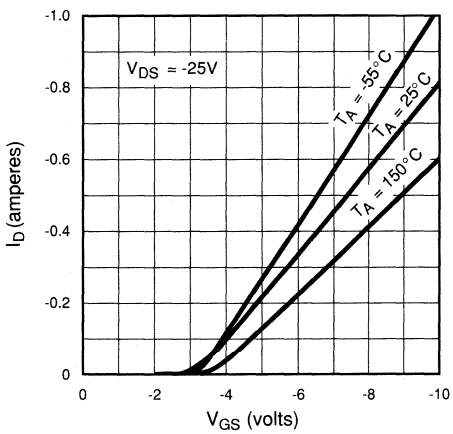
BV$_{DSS}$ Variation with Temperature



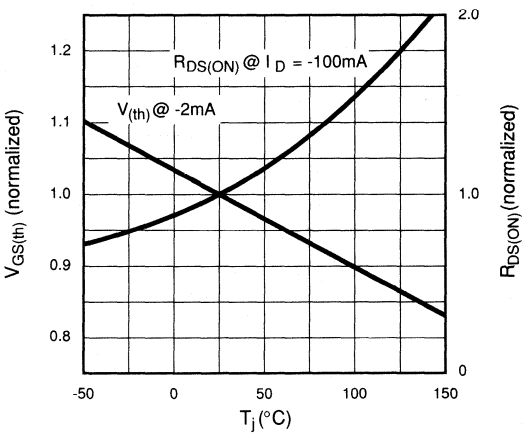
On-Resistance vs. Drain Current



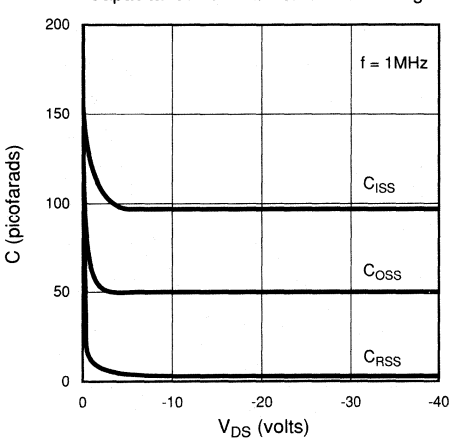
Transfer Characteristics



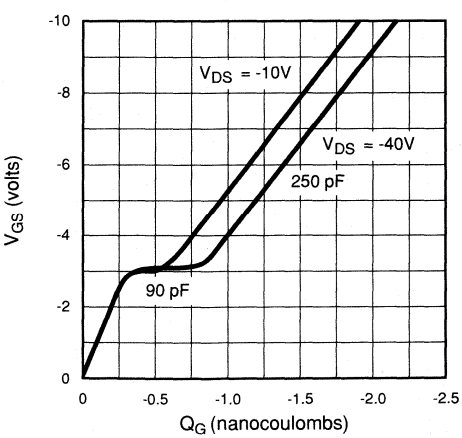
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
			TO-39	TO-92
-80V	5Ω	-1.1A	VP0808B	VP0808L
-100V	5Ω	-1.1A	VP1008B	VP1008L

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	±40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

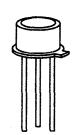
Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

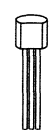
Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

9

Package Options (Note 1)



TO-39



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation	θ_{ja} °C/W	θ_{jc} °C/W
TO-39	-0.88A	-3A	6.25W	170	20
TO-92	-0.21A	-3A	0.4W	312.5	41

* I_D (continuous) is limited by max rated T_j.

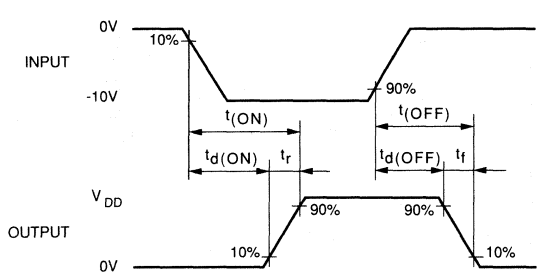
Electrical Characteristics (@ 25°C unless otherwise specified)

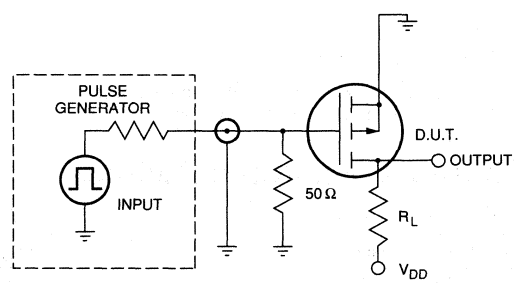
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP1008	-100			V	V_{GS}= 0, I_D =-10μA
		VP0808	-80				
$V_{GS(th)}$	Gate Threshold Voltage		-1.0		-4.5	V	V_{GS} = V_{DS}, I_D = -1mA
I_{GSS}	Gate Body Leakage				100	nA	V_{GS} = 30V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	μA	V_{GS} = 0V, V_{DS} = Max Rating
					-500		V_{GS} = 0, V_{DS} = Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-1.1			A	V_{GS} = -10V, V_{DS} ≥ $2V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance				5	Ω	V_{GS} = -10V, I_D = -1A
G_{FS}	Forward Transconductance		200			m℧	V_{DS} ≥ $2V_{DS(ON)}$, I_D = -0.5A
C_{ISS}	Input Capacitance				150	pF	V_{GS} = 0V, V_{DS} = -25V f = 1MHz
C_{OSS}	Common Source Output Capacitance				60		
C_{RSS}	Reverse Transfer Capacitance				25		
$t_{d(ON)}$	Turn-ON Delay Time				10	ns	V_{DD} = -25V, I_D = -0.5A R_S = 50Ω
t_r	Rise Time				10		
$t_{d(OFF)}$	Turn-OFF Time				10		
t_f	Fall Time				10		
V_{SD}	Diode Forward Voltage Drop	VP1008		1.2		V	V_{GS} = 0, I_{SD} = 0.21A
		VP0808		1.2			V_{GS} = 0, I_{SD} = 0.9A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-220	DICE†
-60V	2Ω	-5A	VP1106N2	VP1106N5	VP1106ND
-100V	2Ω	-5A	VP1110N2	VP1110N5	VP1110ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
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- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

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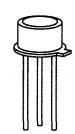
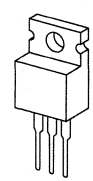
9

Package Options (Note1)



TO-39



TO-220

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	-1.5A	-7A	6W	125	20.8	-1.5A	-7A
TO-220	-4.0A	-12A	45W	70	2.78	-4A	-12A

* I_D (continuous) is limited by max rated T_j.

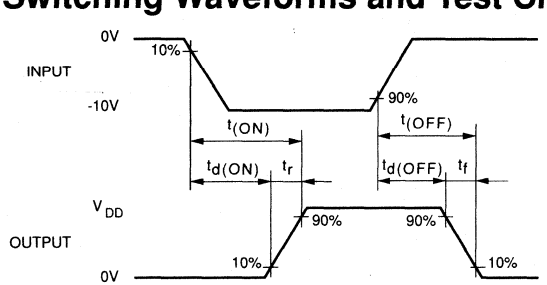
Electrical Characteristics (@ 25°C unless otherwise specified)

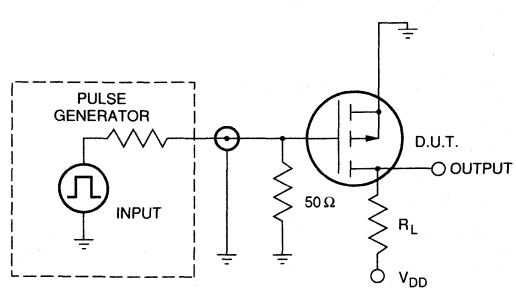
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP1110	-100			V	I_D = -5mA, V_{GS} = 0
		VP1106	-60				
$V_{GS(th)}$	Gate Threshold Voltage		-1.5		-3.5	V	V_{GS} = V_{DS}, I_D = -5mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			4.0		mV/°C	I_D = -5mA, V_{GS} = V_{DS}
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-50	µA	V_{GS} = 0, V_{DS} = Max Rating
					-5	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-1.0			A	V_{GS} = -5V, V_{DS} = -25V
			-5.0				V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			2	5	Ω	V_{GS} = -5V, I_D = -0.5A
				1.5	2		V_{GS} = -10V, I_D = -2.0A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.7	1.0	%/°C	I_D = -1.0A, V_{GS} = -10V
G_{FS}	Forward Transconductance		0.9	1.3		℧	V_{DS} = -25V, I_D = -2.0A
C_{ISS}	Input Capacitance			300	350	pF	V_{GS} = 0, V_{DS} = -20V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			100	150		
C_{RSS}	Reverse Transfer Capacitance			20	35		
$t_{d(ON)}$	Turn-ON Delay Time			35	40	ns	V_{DD} = -18V, I_D = -2.0A, R_S = 50Ω
t_r	Rise Time			20	30		
$t_{d(OFF)}$	Turn-OFF Delay Time			40	50		
t_f	Fall Time			10	20		
V_{SD}	Diode Forward Voltage Drop			-1.4	-2.5	V	I_{SD} = -1.0A, V_{GS} = 0
t_{rr}	Reverse Recovery Time			400		ns	I_{SD} = -1.0A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

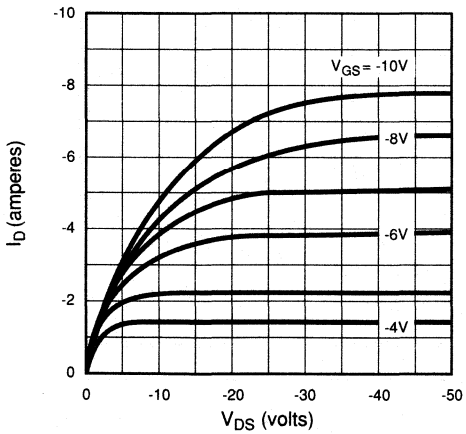
Switching Waveforms and Test Circuit



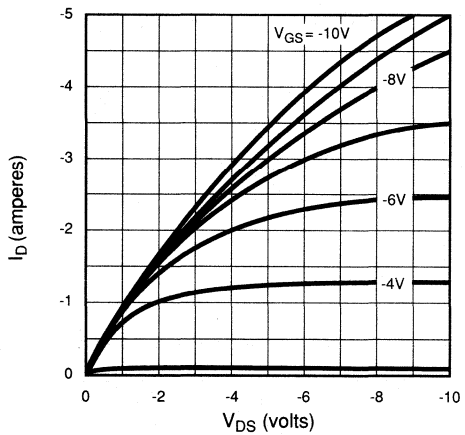


Typical Performance Curves

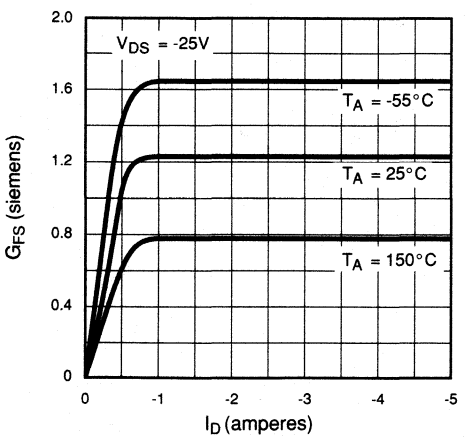
Output Characteristics



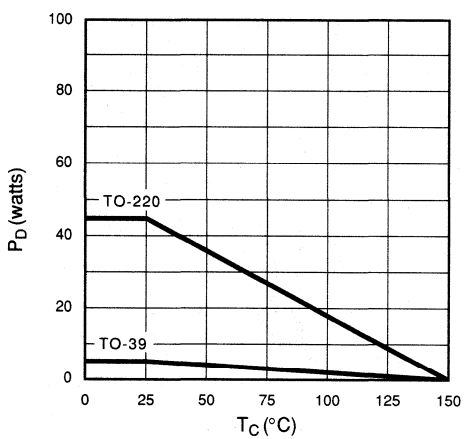
Saturation Characteristics



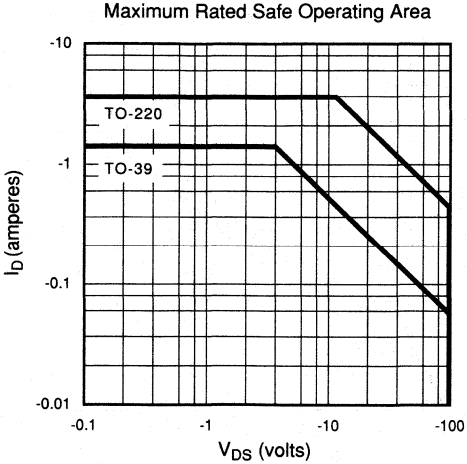
Transconductance vs. Drain Current



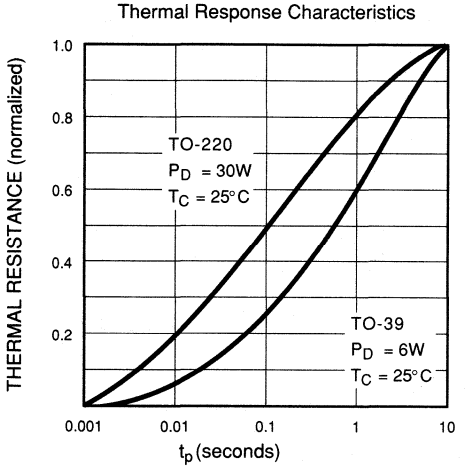
Power Dissipation vs. Case Temperature



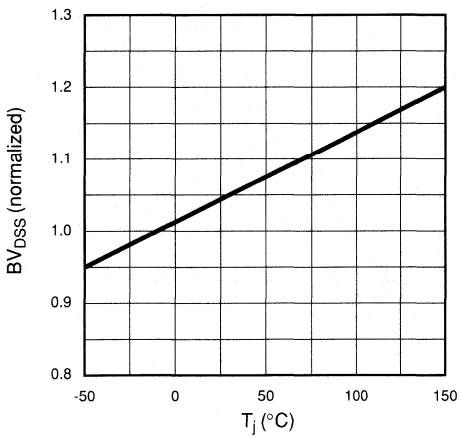
Maximum Rated Safe Operating Area



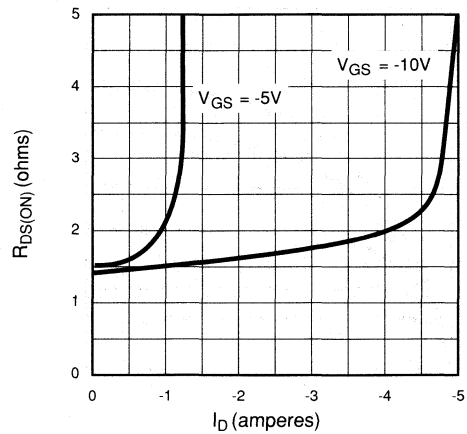
Thermal Response Characteristics



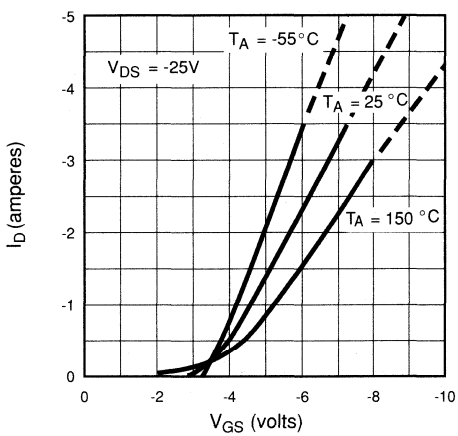
BV$_{DSS}$ Variation with Temperature



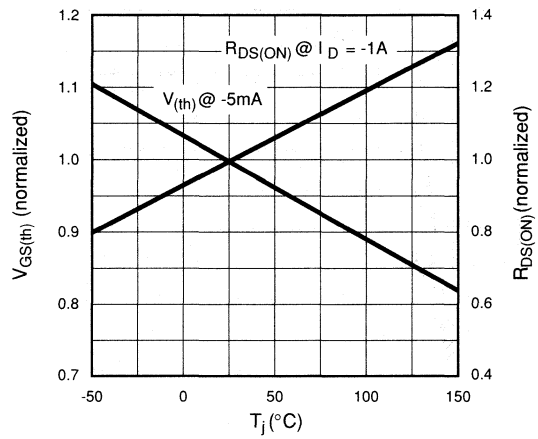
On-Resistance vs. Drain Current



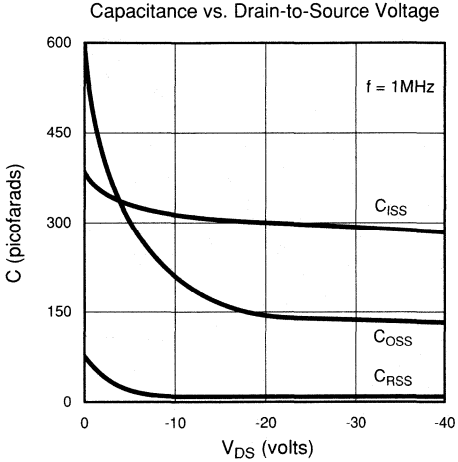
Transfer Characteristics



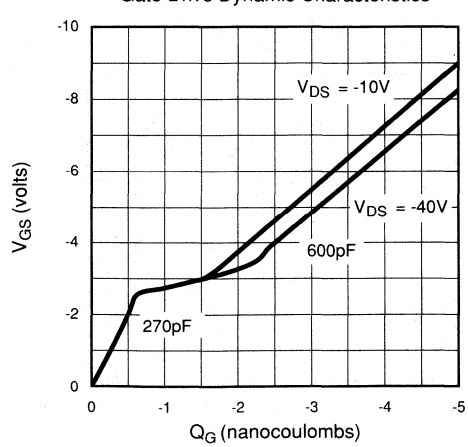
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-220	DICE†
-160V	5Ω	-1.5A	VP1116N2	VP1116N5	VP1116ND
-200V	5Ω	-1.5A	VP1120N2	VP1120N5	VP1120ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

*Distance of 1.6 mm from case for 10 seconds.

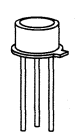
Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

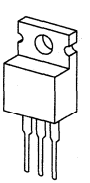
Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options

(Note 1)



TO-39



TO-220

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	-0.8A	-3A	6W	125	20.8	-0.8A	-3A
TO-220	-1.8A	-7A	45W	70	2.7	-1.8A	-7A

* I_D (continuous) is limited by max rated T_j.

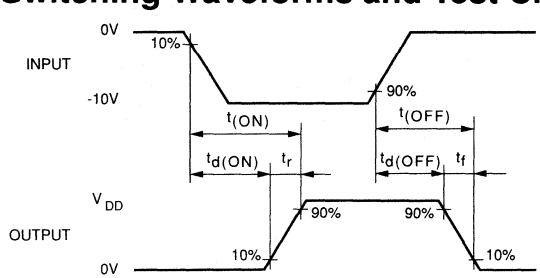
Electrical Characteristics (@ 25°C unless otherwise specified)

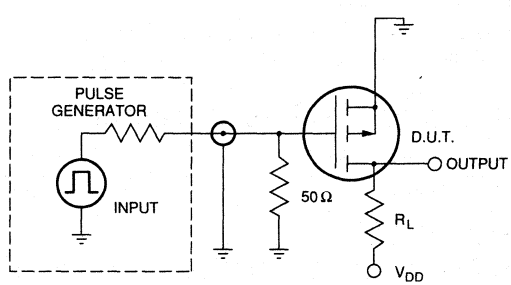
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP1120	-200			V	I_D = -5mA, V_{GS} = 0
		VP1116	-160				
$V_{GS(th)}$	Gate Threshold Voltage		-1.5		-3.5	V	V_{GS} = V_{DS}, I_D = -5mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			3.5	6	mV/°C	I_D = -5mA, V_{GS} = V_{DS}
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-50	µA	V_{GS} = 0, V_{DS} = Max Rating
					-10	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-0.5	-1.4		A	V_{GS} = -5V, V_{DS} = -25V
			-1.5	-4			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			3.3	7	Ω	V_{GS} = -5V, I_D = -0.5A
				3	5		V_{GS} = -10V, I_D = -1.0A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.8	1.2	%/°C	I_D = -1.0A, V_{GS} = -10V
G_{FS}	Forward Transconductance		0.5	0.75		℧	V_{DS} = -25V, I_D = -1.0A
C_{ISS}	Input Capacitance			300	350	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			60	80		
C_{RSS}	Reverse Transfer Capacitance			10	25		
$t_{d(ON)}$	Turn-ON Delay Time			8	25	ns	V_{DD} = -25V, I_D = -1.0A, R_S = 50Ω
t_r	Rise Time			4	20		
$t_{d(OFF)}$	Turn-OFF Delay Time			24	40		
t_f	Fall Time			8	20		
V_{SD}	Diode Forward Voltage Drop			-1.2	-2.0	V	I_{SD} = -1.0A, V_{GS} = 0
t_{rr}	Reverse Recovery Time			350		ns	I_{SD} = -1.0A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

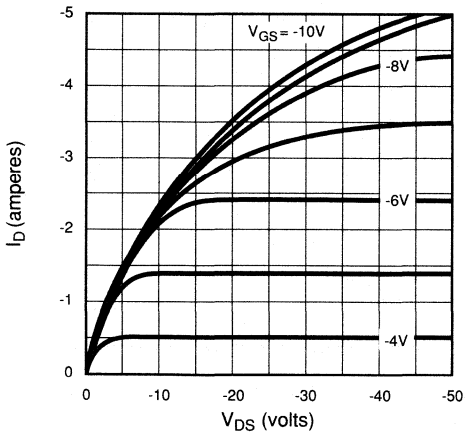
Switching Waveforms and Test Circuit



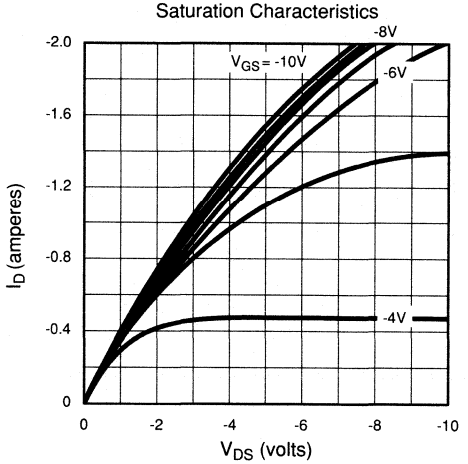


Typical Performance Curves

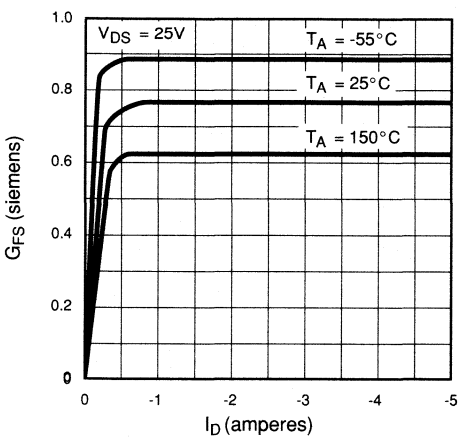
Output Characteristics



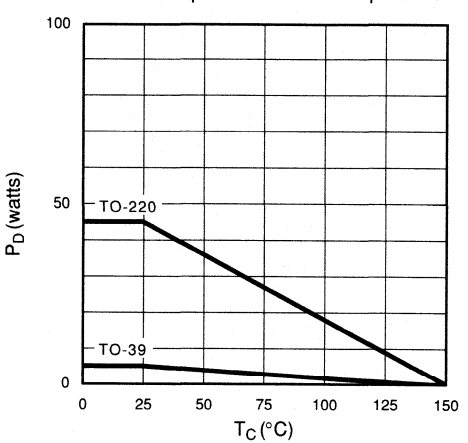
Saturation Characteristics



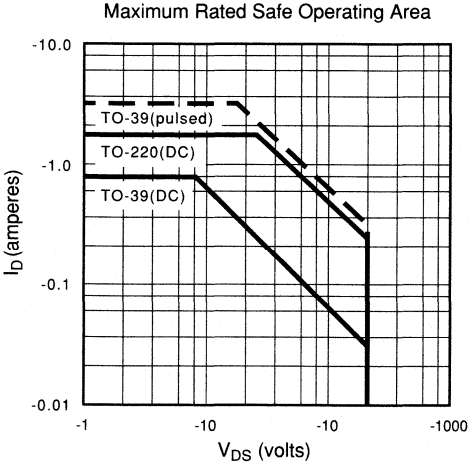
Transconductance vs. Drain Current



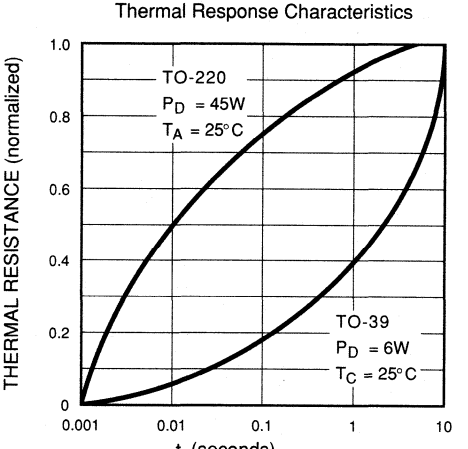
Power Dissipation vs. Case Temperature



Maximum Rated Safe Operating Area

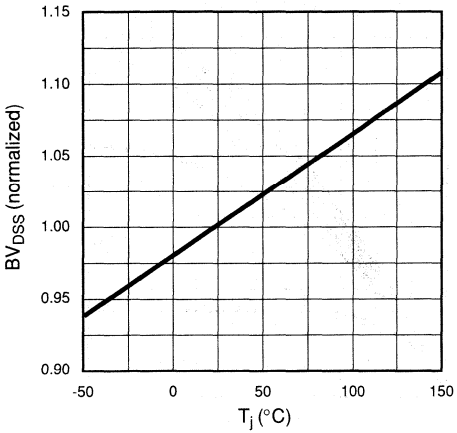


Thermal Response Characteristics

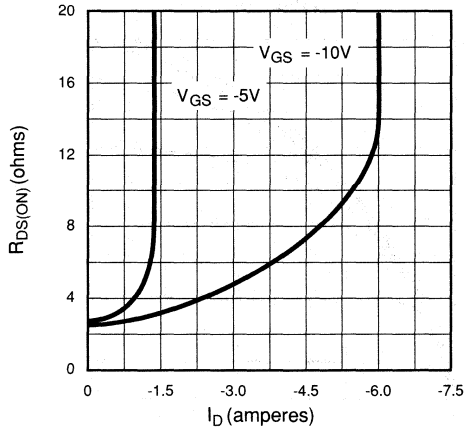


9

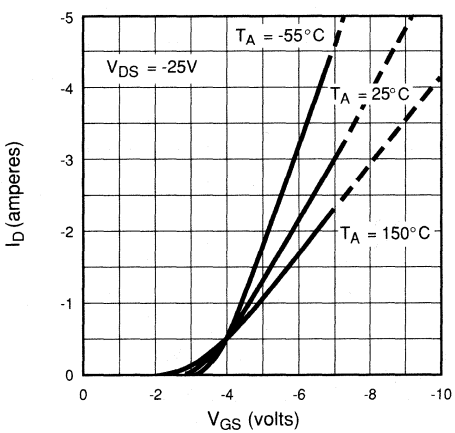
BV$_{DSS}$ Variation with Temperature



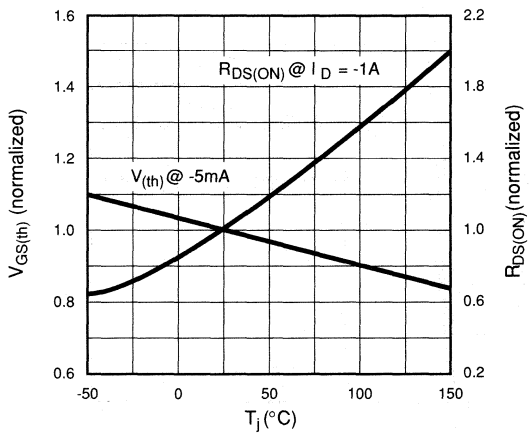
On-Resistance vs. Drain Current



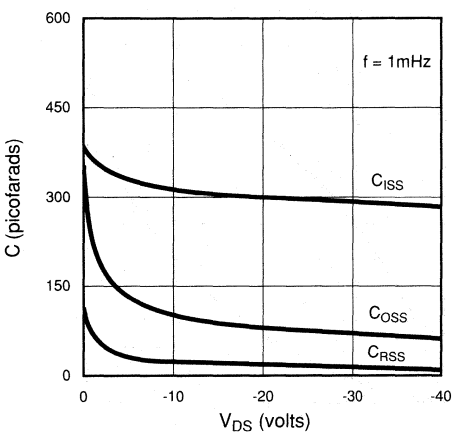
Transfer Characteristics



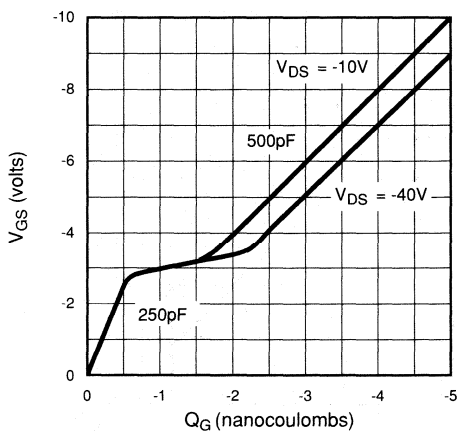
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-220	DICE†
-40V	0.8Ω	-6A	VP1204N2	VP1204N5	VP1204ND
-60V	0.8Ω	-6A	VP1206N2	VP1206N5	VP1206ND
-100V	0.8Ω	-6A	VP1210N2	VP1210N5	VP1210ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

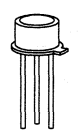
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

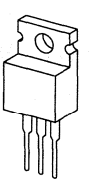
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-39



TO-220

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	-2.5A	-11A	6.5W	125	20	-2.5A	-11A
TO-220	-5.0A	-14A	45W	70	2.75	-5A	-14A

* I_D (continuous) is limited by max rated T_j.

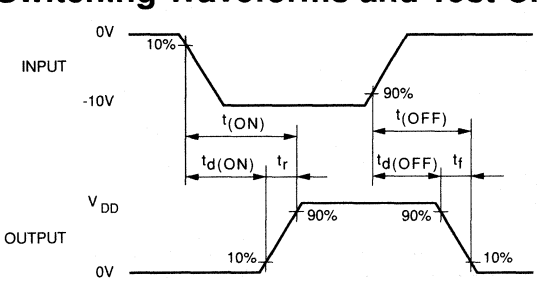
Electrical Characteristics (@ 25°C unless otherwise specified)

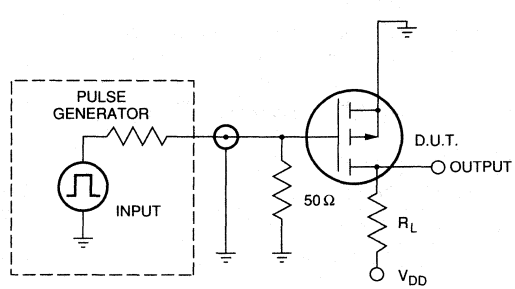
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP1210	-100			V	I_D = -10mA, V_{GS} = 0
		VP1206	-60				
		VP1204	-40				
$V_{GS(th)}$	Gate Threshold Voltage		-1.5		-3.5	V	V_{GS} = V_{DS}, I_D = -10mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			4.7	5.5	mV/°C	I_D = -10mA, V_{GS} = V_{DS}
I_{GSS}	Gate Body Leakage			-1.0	-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-100	µA	V_{GS} = 0, V_{DS} = Max Rating
					-10	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-1.5	-2.0		A	V_{GS} = -5V, V_{DS} = -25V
			-6.0	-12.0			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			1.0	1.4	Ω	V_{GS} = -5V, I_D = -1A
				0.5	0.8		V_{GS} = -10V, I_D = -3A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			1.0	1.5	%/°C	I_D = -10A, V_{GS} = -10V
G_{FS}	Forward Transconductance		1	2		℧	V_{DS} = -25V, I_D = -3A
C_{ISS}	Input Capacitance			550	650	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			250	350		
C_{RSS}	Reverse Transfer Capacitance			50	65		
$t_{d(ON)}$	Turn-ON Delay Time			10	30	ns	V_{DD} = -25V, I_D = -4A, R_S = 50Ω
t_r	Rise Time			17	40		
$t_{d(OFF)}$	Turn-OFF Delay Time			70	105		
t_f	Fall Time			35	60		
V_{SD}	Diode Forward Voltage Drop			-1.2	-1.6	V	I_{SD} = -5A, V_{GS} = 0
t_{rr}	Reverse Recovery Time			500		ns	I_{SD} = -1A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

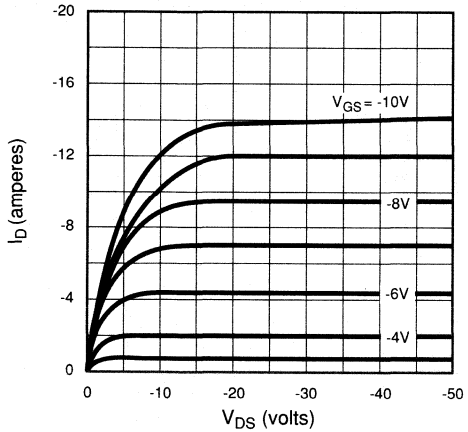
Switching Waveforms and Test Circuit



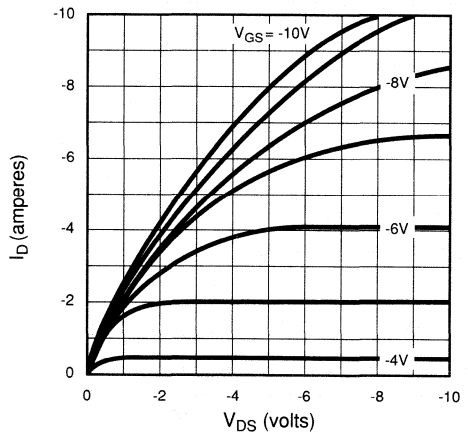


Typical Performance Curves

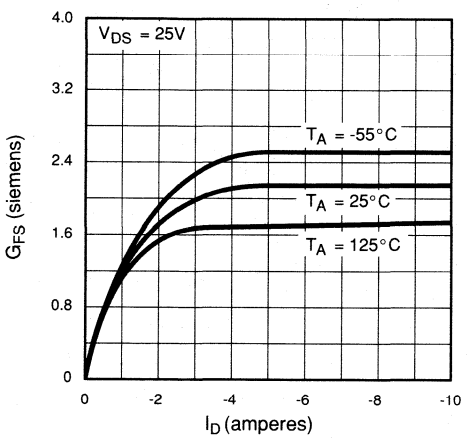
Output Characteristics



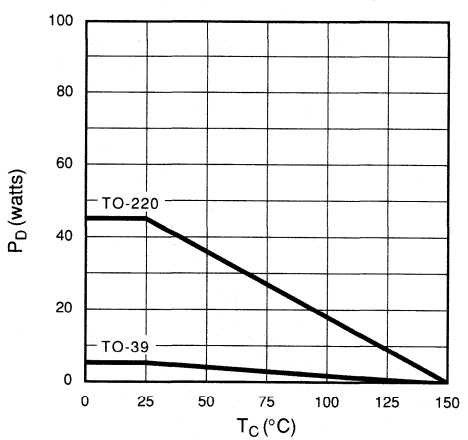
Saturation Characteristics



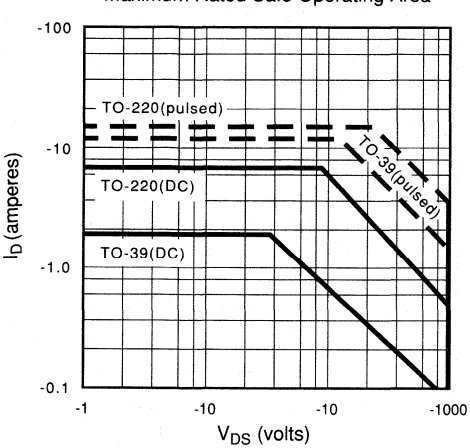
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

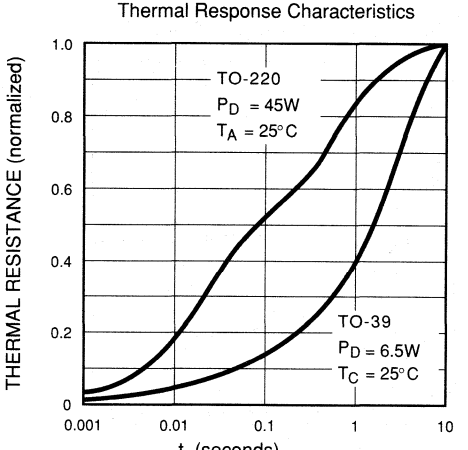


Maximum Rated Safe Operating Area



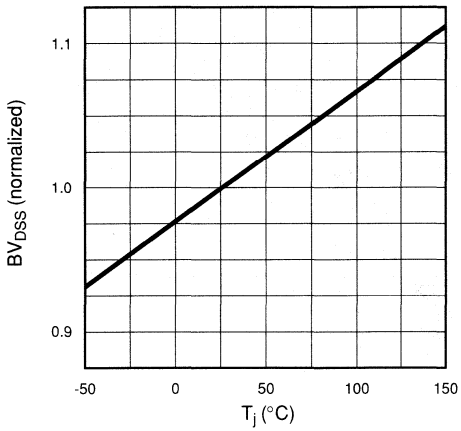
Pulse Condition: 300μs, 2% dutycycle

Thermal Response Characteristics

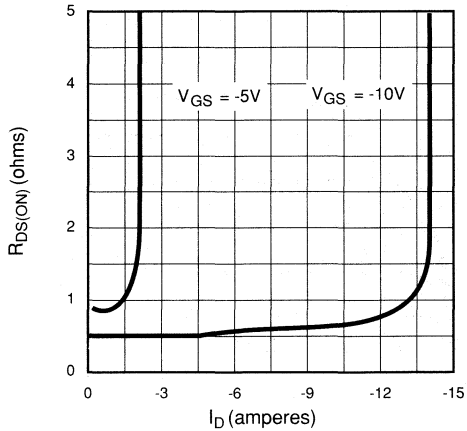


9

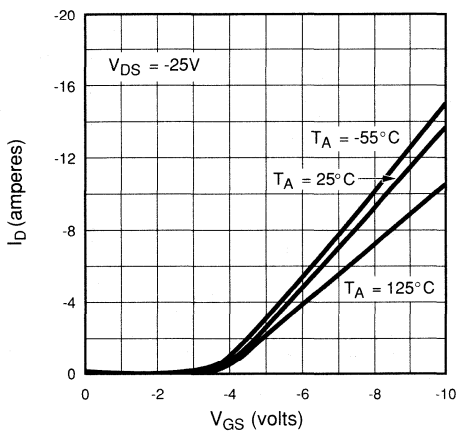
BV$_{DSS}$ Variation with Temperature



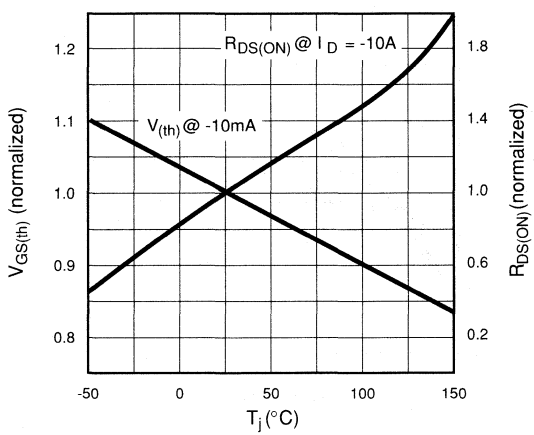
On-Resistance vs. Drain Current



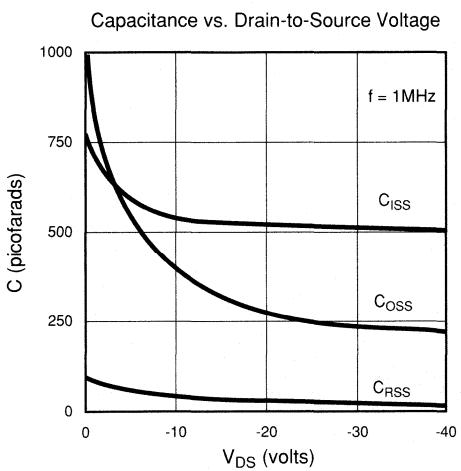
Transfer Characteristics



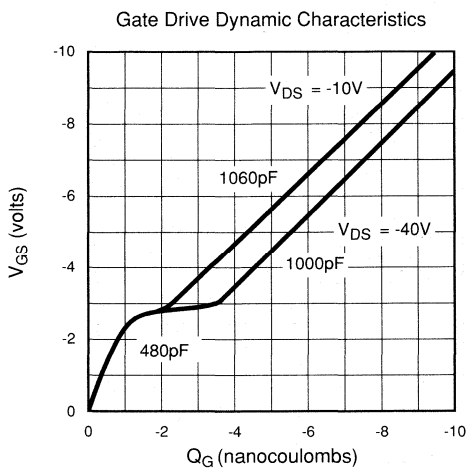
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package		
			TO-39	TO-220	DICE†
-160V	2.5Ω	-4.0A	VP1216N2	VP1216N5	VP1216ND
-200V	2.5Ω	-4.0A	VP1220N2	VP1220N5	VP1220ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

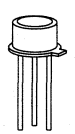
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

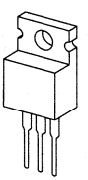
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-39



TO-220

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	-2.0A	-4.5A	6.5W	125	20	-2.0A	-4.5A
TO-220	-3.5A	-6.0A	45W	70	2.75	-3.5A	-6.0A

* I_D (continuous) is limited by max rated T_j.

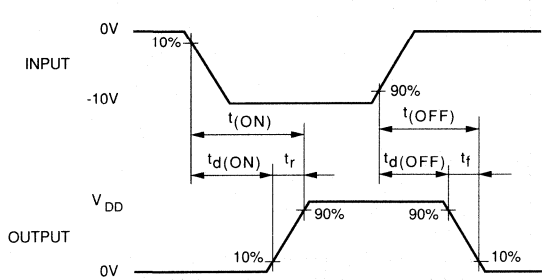
Electrical Characteristics (@ 25°C unless otherwise specified)

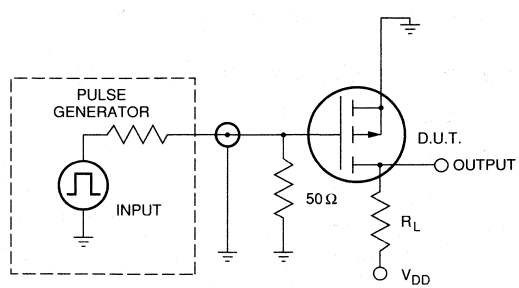
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP1220	-200			V	V_{GS} = 0, I_D = -10mA
		VP1216	-160				
$V_{GS(th)}$	Gate Threshold Voltage		-1.5		-3.5	V	V_{GS} = V_{DS}, I_D = -10mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			3.5	4.5	mV/°C	V_{GS} = V_{DS}, I_D = -10mA
I_{GSS}	Gate Body Leakage				-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			-1.0	-100	µA	V_{GS} = 0, V_{DS} = Max Rating
					-10	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-.0.5	-1.0		A	V_{GS} = -5V, V_{DS} = -25V
			-4.0	-7.0			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			2.0	4.0	Ω	V_{GS} = -5V, I_D = -0.5A
				1.6	2.5		V_{GS} = -10V, I_D = -1.0A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.5	1.0	%/°C	V_{GS} = -10V, I_D = -1A
G_{FS}	Forward Transconductance		0.8	1.2		℧	V_{DS} = -25V, I_D = -3.0A
C_{ISS}	Input Capacitance			600	700	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			200	250		
C_{RSS}	Reverse Transfer Capacitance			20	30		
$t_{d(ON)}$	Turn-ON Delay Time			30	40	ns	V_{DD} = -15V, I_D = -2.0A, R_S = 50Ω
t_r	Rise Time			26	35		
$t_{d(OFF)}$	Turn-OFF Delay Time			45	90		
t_f	Fall Time			20	40		
V_{SD}	Diode Forward Voltage Drop			-1.4	-2.0	V	I_{SD} = -0.5A, V_{GS} = 0
t_{rr}	Reverse Recovery Time			500		ns	I_{SD} = -0.5A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

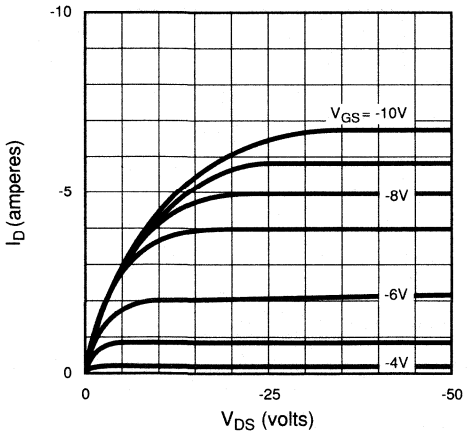
Switching Waveforms and Test Circuit



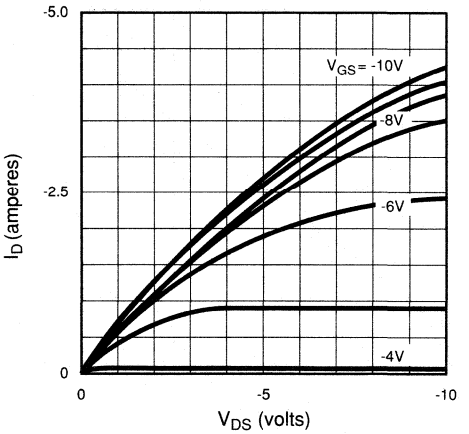


Typical Performance Curves

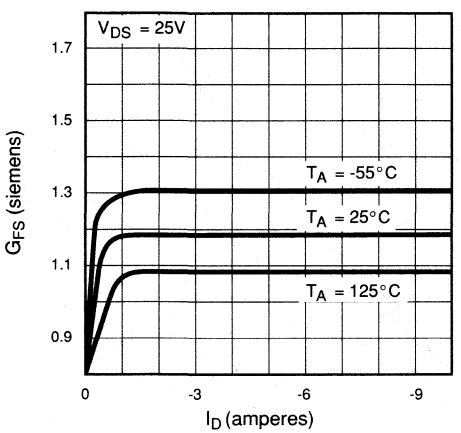
Output Characteristics



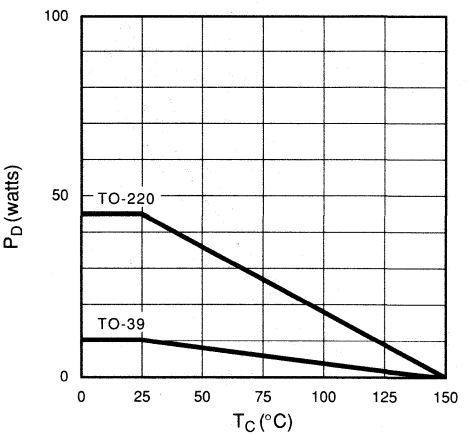
Saturation Characteristics



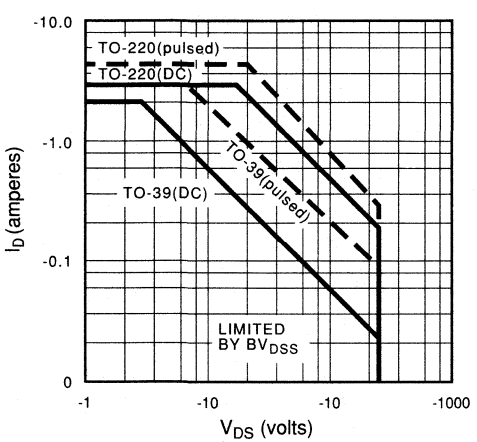
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

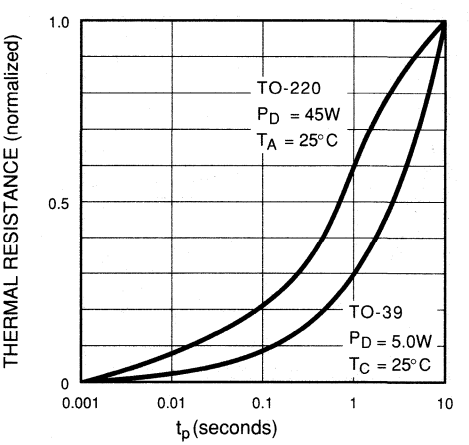


Maximum Rated Safe Operating Area



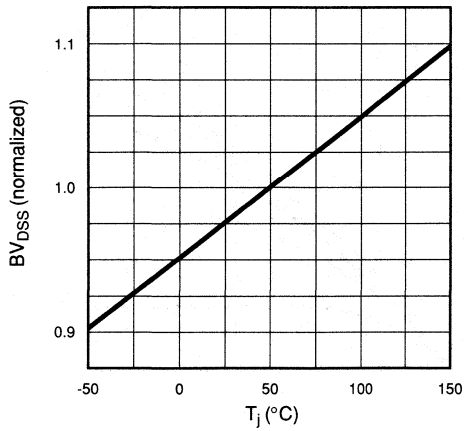
Pulse Condition: 300µs, 2% dutycycle

Thermal Response Characteristics

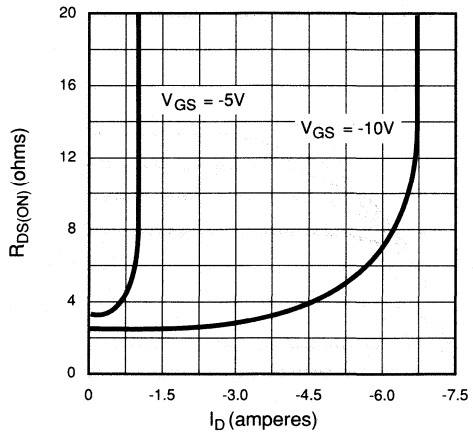


9

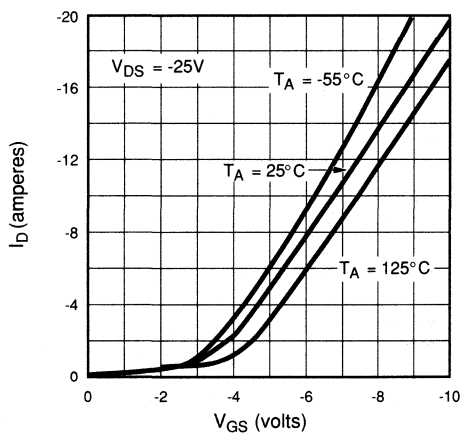
BV$_{DSS}$ Variation with Temperature



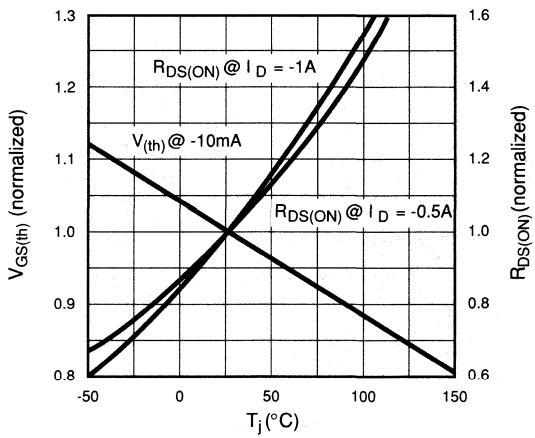
On-Resistance vs. Drain Current



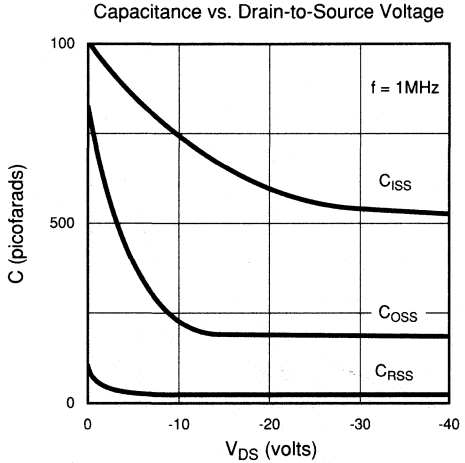
Transfer Characteristics



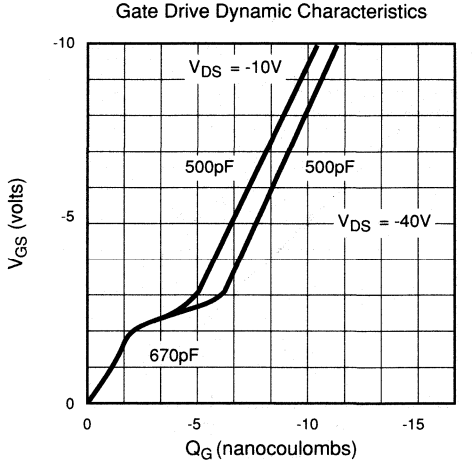
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
			TO-39	TO-92
-40V	25Ω	-0.25A	VP1304N2	VP1304N3
-60V	25Ω	-0.25A	VP1306N2	VP1306N3
-100V	25Ω	-0.25A	VP1310N2	VP1310N3

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

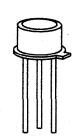
*Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

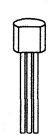
These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-39



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-39	-0.25A	-0.8A	3.0W	125	41	-0.25A	-0.8A
TO-92	-0.15A	-0.65A	0.8W	170	155	-0.15A	-0.65A

* I_D (continuous) is limited by max rated T_j.

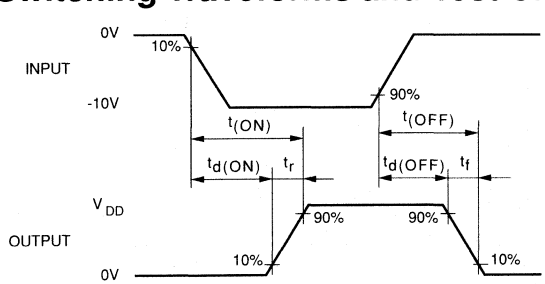
Electrical Characteristics (@ 25°C unless otherwise specified)

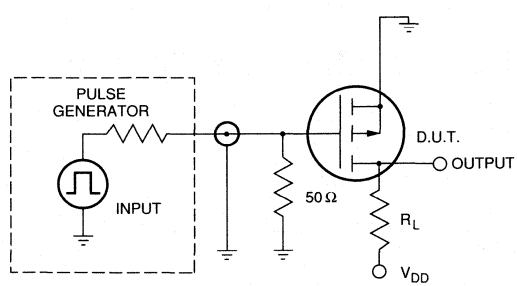
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP1310	-100			V	I_D = -1mA, V_{GS} = 0
		VP1306	-60				
		VP1304	-40				
$V_{GS(th)}$	Gate Threshold Voltage		-1.5		-3.5	V	V_{GS} = V_{DS}, I_D = -1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.2	-3.85	mV/°C	V_{GS} = V_{DS}, I_D = -1mA
I_{GSS}	Gate Body Leakage			-0.1	-100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-10	μA	V_{GS} = 0, V_{DS} = Max Rating
					-500		V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-.08	-0.23		A	V_{GS} = -5V, V_{DS} = -25V
			-0.25	-0.65			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			30	40	Ω	V_{GS} = -5V, I_D = -50mA
				16	25		V_{GS} = -10V, I_D = -250mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.8	1.1	%/°C	I_D = -250mA, V_{GS} = -10V
G_{FS}	Forward Transconductance		75	120		m℧	V_{DS} = -25V, I_D = -200mA
C_{ISS}	Input Capacitance			20	35	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			12	15		
C_{RSS}	Reverse Transfer Capacitance			3	5		
$t_{d(ON)}$	Turn-ON Delay Time			3	5	ns	V_{DD} = -25V, I_D = -200mA, R_S = 50Ω
t_r	Rise Time			3	5		
$t_{d(OFF)}$	Turn-OFF Delay Time			3	5		
t_f	Fall Time			3	5		
V_{SD}	Diode Forward Voltage Drop			-1.2	-1.7	V	I_{SD} = -1A, V_{GS} = 0
t_{rr}	Reverse Recovery Time			350		ns	I_{SD} = -1A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

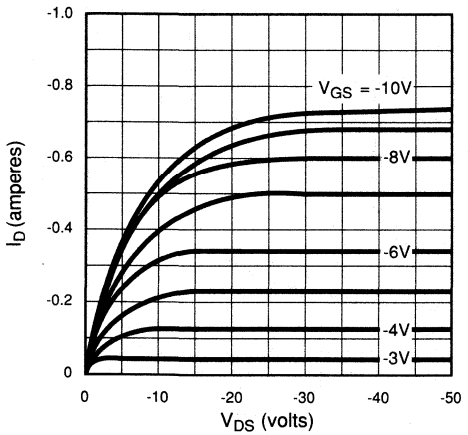
Switching Waveforms and Test Circuit



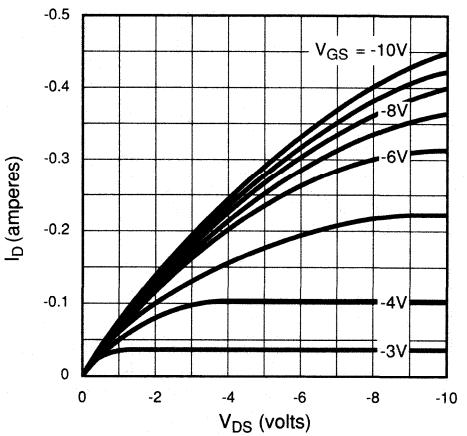


Typical Performance Curves

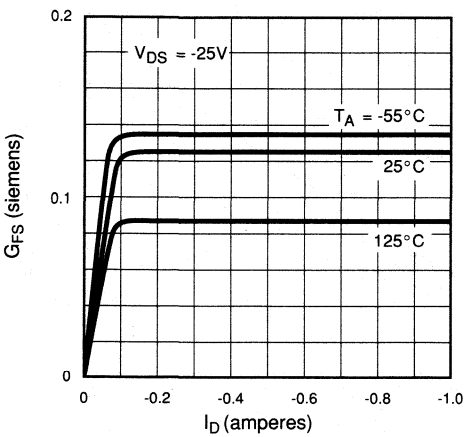
Output Characteristics



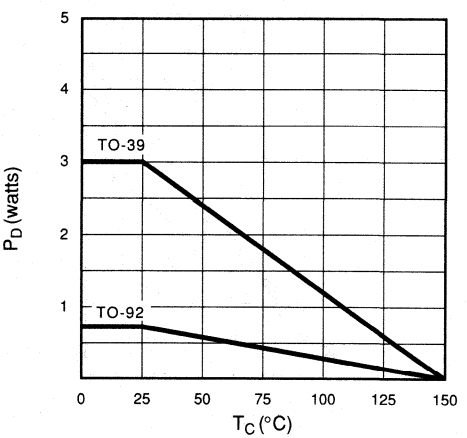
Saturation Characteristics



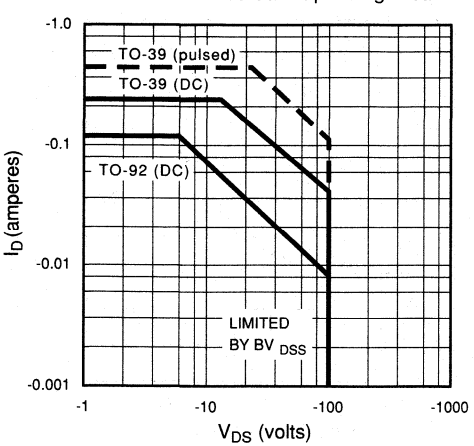
Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature

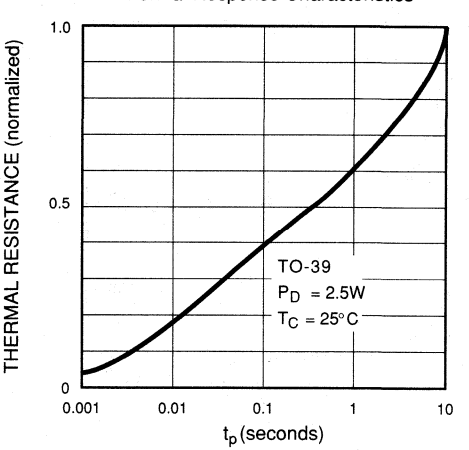


Maximum Rated Safe Operating Area



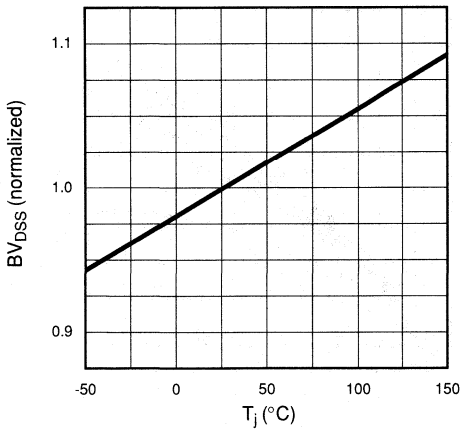
Pulsed Condition: 300 µs; 2% Duty Cycle

Thermal Response Characteristics

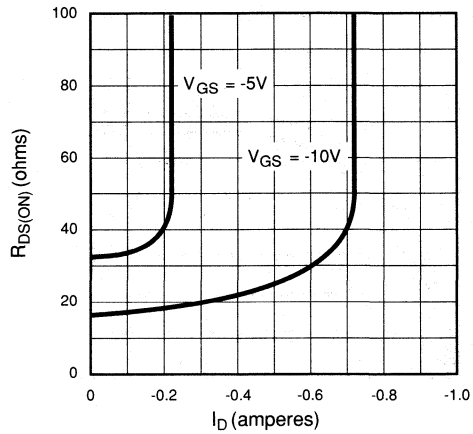


9

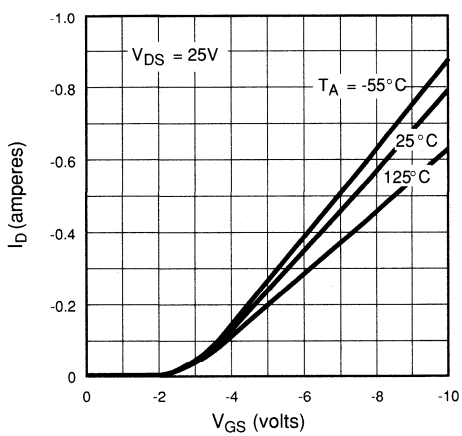
BV$_{DSS}$ Variation with Temperature



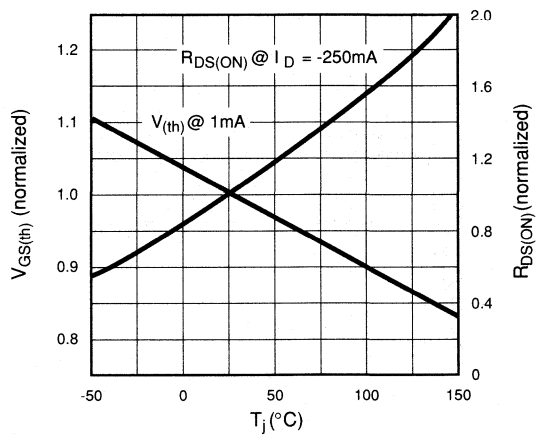
On-Resistance vs. Drain Current



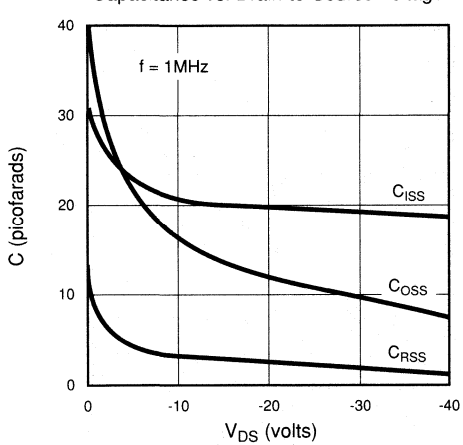
Transfer Characteristics



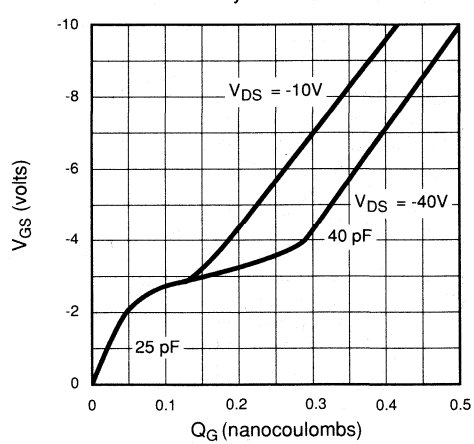
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics



P-Channel Enhancement-Mode Vertical DMOS FETs

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
			TO-92	DICE†
40V	0.9Ω	-4A	VP2204N3	VP2204ND
60V	0.9Ω	-4A	VP2206N3	VP2206ND
-100V	0.9Ω	-4A	VP2210N3	VP2210ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Converters
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Drivers (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	±20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

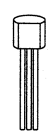
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) power transistors utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermallyinduced secondary breakdown.

Supertex Vertical DMOS FETs are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Package Options (Note 1)



TO-92

Note 1: See Package Outline section for discrete pinouts.

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}*	I_{DRM}
TO-92	-0.65A	-4.0A	1.0W	170	125	-0.65A	-4.0A

* I_D (continuous) is limited by max rated T_j.

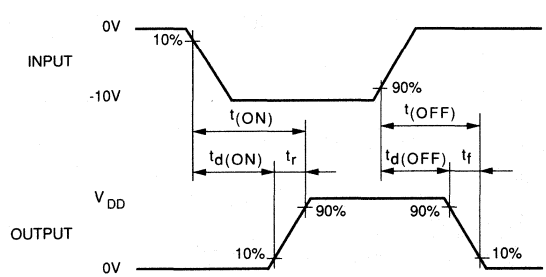
Electrical Characteristics (@ 25°C unless otherwise specified)

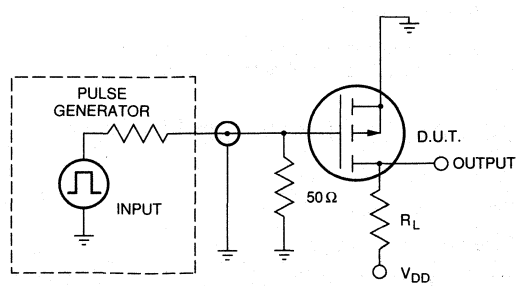
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VP2204	-40			V	V_{GS} = 0, I_D = -10mA
		VP2206	-60				
		VP2210	-100				
$V_{GS(th)}$	Gate Threshold Voltage		-1.0		-3.5	V	V_{GS} = V_{DS}, I_D = -10mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			4.3	5.5	mV/°C	V_{GS} = V_{DS}, I_D = -10mA
I_{GSS}	Gate Body Leakage			-1	-100	nA	V_{GS} = ± 20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				-50	µA	V_{GS} = 0, V_{DS} = Max Rating
					-10	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		-1.5	-2		A	V_{GS} = -5V, V_{DS} = -25V
			-4	-8			V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			1.3	1.5	Ω	V_{GS} = -5V, I_D = -1A
				0.75	0.9		V_{GS} = -10V, I_D = -3.5A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.85	1.2	%/°C	V_{GS} = -10V, I_D = -3.5A
G_{FS}	Forward Transconductance		0.8	1.2		℧	V_{DS} = -25V, I_D = -2A
C_{ISS}	Input Capacitance				450	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance				180		
C_{RSS}	Reverse Transfer Capacitance				40		
$t_{d(ON)}$	Turn-ON Delay Time			10	15	ns	V_{DD} = -25V, I_D = -3.5A, R_S = 50Ω
t_r	Rise Time			10	15		
$t_{d(OFF)}$	Turn-OFF Delay Time			30	50		
t_f	Fall Time			30	50		
V_{SD}	Diode Forward Voltage Drop			-1.2	-1.6	V	V_{GS} = 0, I_{SD} = -3.5A
t_{rr}	Reverse Recovery Time			500		ns	V_{GS} = 0, I_{SD} = -1A

Note 1: All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300µs pulse, 2% duty cycle.)
Note 2: All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





MOSFET Array Selector Guide

Low Voltage N-Channel

Device No.[1]	Number of Channels/Type	BV_{DSS} Min (V)	$R_{DS(ON)}$ Max (Ω)	Package Options				
				Plastic Dip	Ceramic Dip	SOW-20	Ceramic LCC	Die
VN0104	4N	40	3	•	•			•
VN0106	4N	60	3	•	•			•
TN0604	4N	40	1.0			•		•
TN0606	4N	60	1.5	•	•			•
VN2106	4N	60	3				•	•
VN2110	4N	100	3				•	•
VQ1000	4N	60	5.5	•	•			•
VQ1001	4N	30	1		•			•
VQ1004	4N	60	3.5	•	•			•

Note 1: Excluding package suffix.

Low Voltage P-Channel

Device No.[1]	Number of Channels/Type	BV_{DSS} Min (V)	$R_{DS(ON)}$ Max (Ω)	Package Options				
				Plastic Dip	Ceramic Dip	SOW-20	Ceramic LCC	Die
VP0104	4P	40	8	•	•			•
VP0106	4P	60	8	•	•			•
TP0604	4P	40	2			•		•
TP0606	4P	60	3.5	•	•			•
VQ2001	4P	30	2		•			•
VQ2006	4P	90	5		•			•

Note 1: Excluding package suffix.

Low Voltage Complementary

Device No.[1]	Number of Channels/Type	BV_{DSS} Min (V)	$R_{DS(ON)}$ Max (Ω)	Package Options				
				Plastic Dip	Ceramic Dip	SOW-20	Ceramic LCC	Die
TC0604	2N + 2P	40	3.0[2]			•		•
VC0106	2N + 2P	60	11.0[2]	•	•			•
TQ3001	2N + 2P	40	3.0[2]	•	•		•	•
VQ3001	2N + 2P	40	3.0[2]	•	•		•	•
VQ7254	2N + 2P	20	3.0[2]	•	•			•

Note 1: Excluding package suffix.
Note 2: One N-channel plus one P-channel

Supertex inc.

MOSFET Array Selector Guide

High Voltage [2]

Device No.[1]	Number of Channels/Type	BV_{DSS} Min (V)	$R_{DS\ (ON)}$ Max (Ω)	Package Options		
				Plastic Dip	SOW-20	Die
AN0120	8N	200	300	•		•
AN0130	8N	300	300	•		•
AN0140	8N	400	350	•	•	•
AN0420	8N	200	300	•		•
AN0430	8N	300	300	•		•
AN0440	8N	400	350	•	•	•
AP0120	8P	-200	600	•		•
AP0130	8P	-300	600	•		•
AP0140	8P	-400	700	•	•	•
AP0420	8P	-200	600	•		•
AP0430	8P	-300	600	•		•
AP0440	8P	-400	700	•	•	•

Notes:
1. Excluding package suffix.
2. Monolithic 8 Channel Array.

High Voltage Low Leakage [2,3]

Device No.[1]	Number of Channels/Type	BV_{DSS} Min (V)	$R_{DS\ (ON)}$ Max (Ω)	Package Options		
				Plastic Dip	SOW-20	Die
AN0116	8N	160	350	•	•	•
AN0132	8N	320	350	•	•	•
AN0416	8N	160	350	•	•	•
AN0432	8N	320	350	•	•	•
AN0516	8N	160	350	•	•	•
AN0532	8N	320	350	•	•	•
AP0116	8P	-160	700	•	•	•
AP0132	8P	-320	700	•	•	•
AP0416	8P	-160	700	•	•	•
AP0432	8P	-320	700	•	•	•
AP0516	8P	-160	700	•	•	•
AP0532	8P	-320	700	•	•	•

Notes:
1. Excluding package suffix.
2. Monolithic 8 Channel Array.
3. Low I_{DSS} Leakage (refer to data sheet for details).

High Voltage Level Translators

Device No.[1]	Number of Channels	V_{PP} Max (V)	I_{SOURCE} Min (mA)	I_{SINK} Min (mA)	Package Options			
					Plastic Dip	Ceramic Dip	SOW-20	Die
HT0130	8	300	0.2	0.1	.	.	.	.

Notes:
1. Excluding package suffix.

8 Channel MOSFET Array
Monolithic N-Channel Enchancement Mode

Ordering Information

BV_{DSS}/ BV_{DGS} (min)	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	I_{DSS}** @ V_{DS} = 100V Max	I_{DSS}** @ V_{DS} = 250V Max	Order Number / Package		
					18-Lead Plastic DIP	Plastic SOW-20*	Die†
160V	350Ω	25mA	1nA	—	AN0116NA	AN0116WG	AN0116ND
200V	300Ω	25mA	—	—	AN0120NA	—	AN0120ND
300V	300Ω	25mA	—	—	AN0130NA	—	AN0130ND
320V	350Ω	25mA	—	1nA	AN0132NA	AN0132WG	AN0132ND
400V	350Ω	25mA	—	—	AN0140NA	AN0140WG	AN0140ND

* Same as SO-20 with 300 mil wide body.
** Average current per channel, measured with all eight channels connected in parallel.
† MIL visual screening available

Features

- ☐ Low drain to source leakage for AN0116 and AN0132
- ☐ 160-volt to 400-volt capability
- ☐ Interfaces directly to CMOS logic
- ☐ 8 independent channels
- ☐ Low crosstalk between channels
- ☐ Low power dissipation
- ☐ Pin compatible with industry standard driver array
- ☐ Free from Secondary breakdown

Applications

- ☐ High impedance/low leakage measurements for Bare Board Testers
- ☐ High voltage piezoelectric transducer drivers
- ☐ High voltage electroluminescent panel drivers
- ☐ High voltage electrostatic array drivers
- ☐ General multi-channel driver array

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C
Channel-to-Channel Crosstalk	10mV/V

* Distance of 1.6 mm from case for 10 seconds.

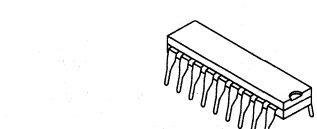
General Description

The Supertex AN01 series of high voltage arrays is designed to provide the interface between MOS logic and loads requiring high voltages and intermediate currents. Each circuit consists of eight channels in a common-source configuration with open drains. This design minimizes the number of package leads needed.

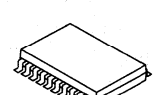
The AN0116 and AN0132 are ideally suited for low leakage/high impedance measurement, providing excellent accuracy and resolution for Automatic Test Equipment.

10

Package Options



18-Lead DIP



SOW-20

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)*	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}	I_{DRM}*
18 lead plastic	30mA	75mA	1.5W	135	83	30mA	75mA
SOW - 20	30mA	75mA	1.4W	110	—	30mA	75mA

* I_D (continuous) is limited by max rated T_j.

Electrical Characteristics (@ 25°C unless otherwise specified)

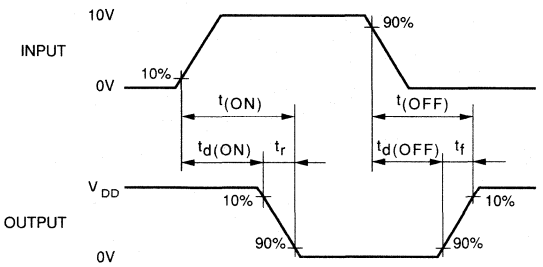
(Notes 1, 2 and 3)

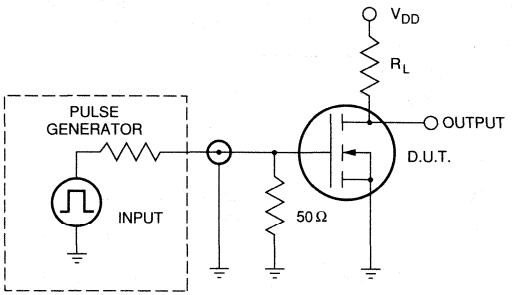
Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	AN0116	160			V	V_{GS} = 0, I_D = 2mA
		AN0120	200				
		AN0130	300				
		AN132	320				
		AN0140	400				
$V_{GS(th)}$	Gate Threshold Voltage		2		5	V	V_{GS} = V_{DS}, I_D = 2mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature				-3.5	mV/°C	V_{GS} = V_{DS}, I_D = 2mA
I_{GSS}	Gate Body Leakage	AN0120					
		AN0130			10	nA	V_{GS} = ±20V, V_{DS} = 0
		AN0140					
		AN0116			1	nA	V_{GS} = ±20V, V_{DS} = 0(3)
		AN0132					
I_{DSS}	Zero Gate Voltage Drain Current	AN0120			1	µA	V_{GS} = 0, V_{DS} = Max Rating(3)
		AN0130			1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating
		AN0140					T_A = 125°C(3)
		AN0116			1	nA	V_{GS} = ±20V, V_{DS} = 100V(3)
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C(3)
		AN0132			1	nA	V_{GS} = ±20V, V_{DS} = 100V(3)
					1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		25			mA	V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	AN0120			300	Ω	V_{GS}= 10V, I_D = 10mA
		AN0130					
		AN0116			350	Ω	V_{GS}= 10V, I_D = 10mA
		AN0132					
		AN0140					
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature			0.8		%/°C	V_{GS} =10V, I_D = 10mA,
G_{FS}	Forward Transconductance		4.0	8.0		m℧	ΔV_{GS} =1V, I_D = 500mA
C_{ISS}	Input Capacitance			5.0	7.5	pF	V_{GS} = 0, V_{DS} = 25V, f = 1MHz
C_{OSS}	Common Source Output Capacitance			3.0	5.0		
C_{RSS}	Reverse Transfer Capacitance			0.8	1.5		
$t_{d(ON)}$	Turn-ON Delay Time			3		ns	V_{DD} = 25V, I_D = 10mA 50Ω drive, $V_{GS(ON)}$ = 10V
t_r	Rise Time			3			
$t_{d(OFF)}$	Turn-OFF Delay Time			5			
t_f	Fall Time			3			
V_{SD}	Diode Forward Voltage Drop				1.3	V	V_{GS} = 0, I_{SD} = 50mA

Notes:

1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.
3. Average current per channel, measured with all 8 channels connected in parallel.

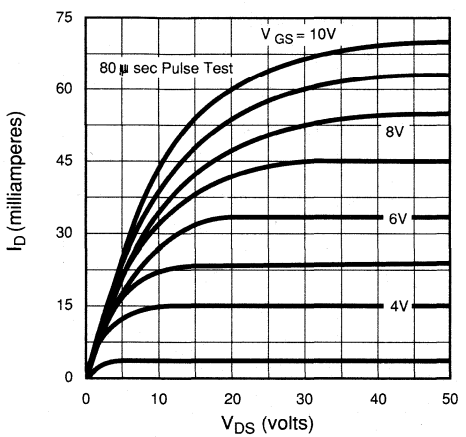
Switching Waveforms and Test Circuit



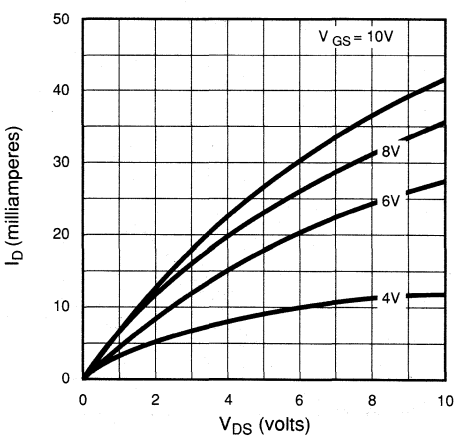


Typical Performance Curves

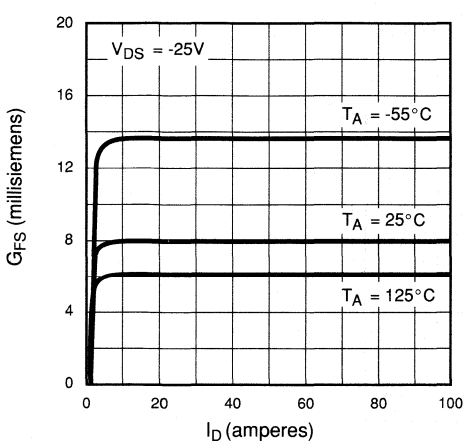
Output Characteristics



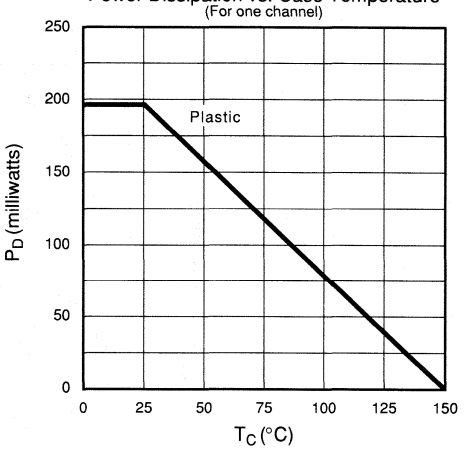
Saturation Characteristics



Transconductance vs. Drain Current



Power Dissipation vs. Case Temperature
(For one channel)



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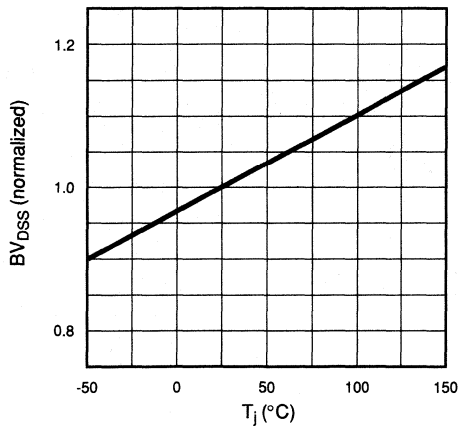
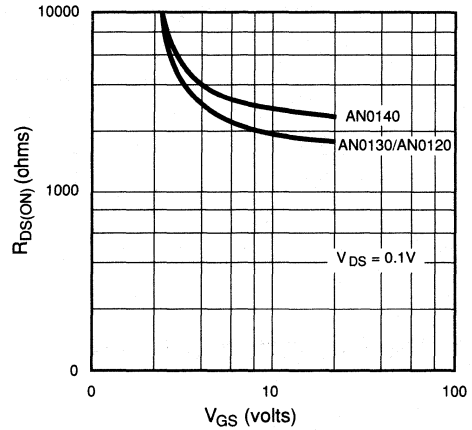
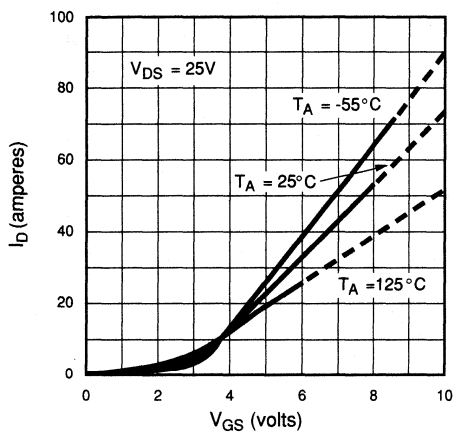
BV$_{DSS}$ Variation with Temperature



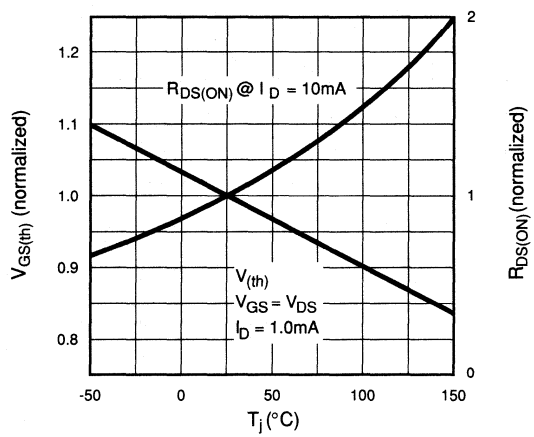
On-Resistance vs. Gate-to-Source Voltage



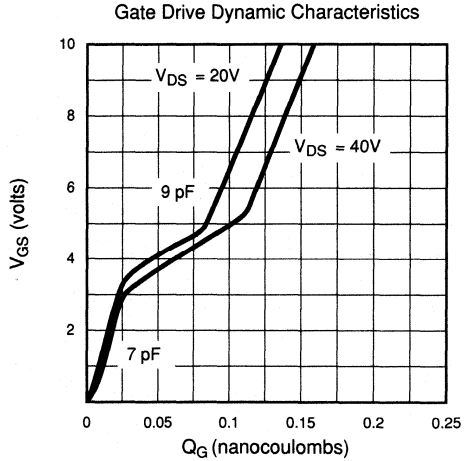
Transfer Characteristics



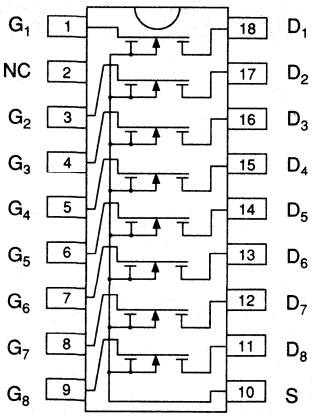
V$_{(th)}$ and R$_{DS}$ Variation with Temperature



Gate Drive Dynamic Characteristics

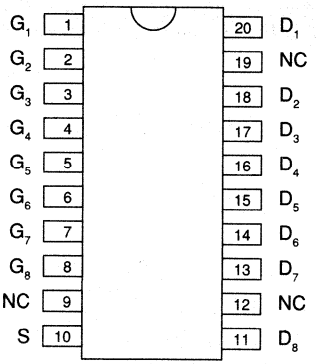


Pin Configuration and Schematic



top view

18-pin DIP



top view

SOW - 20

8 Channel MOSFET Array
Monolithic N-Channel Enchancement Mode

Ordering Information

BV_{DSS}/ BV_{DGS} (min)	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	I_{DSS}** @ V_{DS} = 100V Max	I_{DSS}** @ V_{DS} = 250V Max	Order Number / Package		
					18-Lead Plastic DIP	Plastic SOW-20*	Die†
160V	350Ω	25mA	1nA	—	AN0416NA	AN0416WG	AN0416ND
200V	300Ω	25mA	—	—	AN0420NA	—	AN0420ND
300V	300Ω	25mA	—	—	AN0430NA	—	AN0430ND
320V	350Ω	25mA	—	1nA	AN0432NA	AN0432WG	AN0432ND
400V	350Ω	25mA	—	—	AN0440NA	AN0440WG	AN0440ND

* Same as SO-20 with 300 mil wide body.
** Average current per channel, measured with all eight channels connected in parallel.
† MIL visual screening available

Features

- ☐ ESD Gate Protection
- ☐ Low drain to source leakage for AN0416 and AN0432
- ☐ 160-volt to 400-volt capability
- ☐ Interfaces directly to CMOS logic
- ☐ 8 independent channels
- ☐ Low crosstalk between channels
- ☐ Low power dissipation
- ☐ Pin compatible with industry standard driver array
- ☐ Free from Secondary breakdown

Applications

- ☐ High impedance/low leakage measurements for Bare Board Testers
- ☐ High voltage electroluminescent panel drivers
- ☐ High voltage electrostatic array drivers
- ☐ General multi-channel driver array

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C
Channel-to-Channel Crosstalk	10mV/V

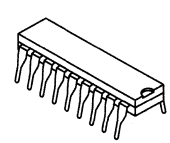
* Distance of 1.6 mm from case for 10 seconds.

General Description

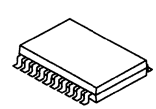
The Supertex AN04 series of high voltage arrays is a ruggedized ESD gate protected version of the Supertex AN01 series. These multichannel arrays meet the EIA ESD standard of 2000V, 100pF capacitor in series with a 1.5KΩ resistor. They are designed to provide the interface between MOS logic and loads requiring high voltages and intermediate currents. Each circuit consists of eight channels in a common-source configuration with open drains. This design minimizes the number of package leads needed.

The AN0416 and AN0432 are ideally suited for low leakage/high impedance measurement, providing excellent accuracy and resolution for Automatic Test Equipment.

Package Options



18-Lead DIP



SOW-20

Thermal Characteristics

Package	I_D(continuous)*	I_D(pulsed)*	Power Dissipation @T_C=25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}	I_{DRM}*
18 lead plastic	30mA	75mA	1.5W	135	83	30mA	75mA
SOW - 20	30mA	75mA	1.4W	110	—	30mA	75mA

* I_D (continuous) is by max rated T_j

Electrical Characteristics (@ 25°C unless otherwise specified)

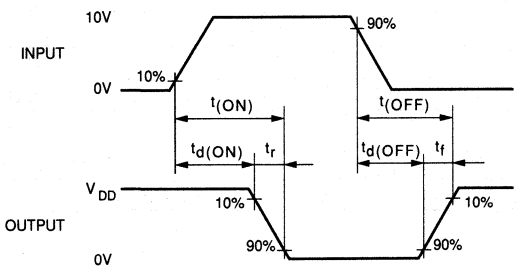
(Note 1, 2 and 3)

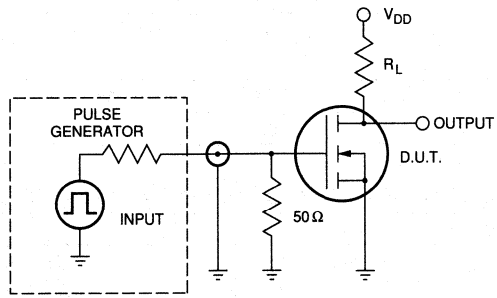
Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	AN0416	160			V	I_D = 100µA, V_{GS}= 0V
		AN0420	200				
		AN0430	300				
		AN0432	320				
		AN0440	400				
$V_{GS(th)}$	Gate Threshold Voltage		2		5	V	V_{GS} = V_{DS}, I_D = 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.5		mV/°C	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage	AN0420 AN0430 AN0440			10	nA	V_{GS} = ±20V, V_{DS} = 0V (3)
		AN0416 AN0432			1	nA	V_{GS} = ±20V, V_{DS} = 0V (3)
I_{DSS}	Zero Gate Voltage Drain Current	AN0420			1	uA	V_{GS} = 0, V_{DS} = Max Rating (3)
		AN0430 AN0440			1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A =125°C (3)
		AN0416			1	nA	V_{GS} = 0V, V_{DS} = 100V (3)
					1	mA	V_{GS} = 0V, V_{DS} = 0.8 Max Rating T_A=125°C (3)
		AN0432			1	nA	V_{GS} = 0V, V_{DS} = 250V (3)
					1	mA	V_{GS} = 0V, V_{DS} = 0.8 Max Rating T_A = 125°C(3)
$I_{D(ON)}$	ON-State Drain Current		25			mA	V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	AN0420 AN0430			300	Ω	V_{GS} = 10V, I_D = 10mA
		AN0416 AN0432 AN0440			350	Ω	V_{GS} = 10V, I_D = 10mA
$\Delta R_{DS(ON)}$	Charge in $R_{DS(ON)}$ with Temperature			0.8		%/°C	V_{GS} = 10V, I_D = 10mA
G_{FS}	Forward Transconductance		4.0	8.0		m℧	ΔV_{GS} = 1V, I_D =10mA
C_{ISS}	Input Capacitance			8.0	12.0	pF	V_{DS} = 25V, V_{GS} = 0V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			5.0	8.0		
C_{RSS}	Reverse Transfer Capacitance			1.3	2.4		
$t_{d(ON)}$	Turn-ON Delay Time			5.0		ns	V_{DS} = 25V, I_D = 10mA, R_S = 50Ω, $V_{GS(ON)}$ = 10V
t_r	Rise Time			5.0			
$t_{d(OFF)}$	Turn-OFF Delay Time			8.0			
t_f	Fall Time			5.0			
V_{SD}	Diode Forward Voltage Drop				1.3	V	V_{GS} = 0V, I_{SD} = 50mA

Notes:

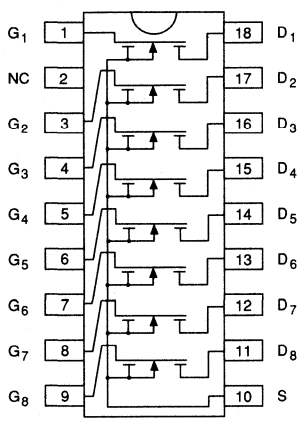
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300mS pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.
3. Average current per channel, measured with all 8 channels connected in parallel.

Switching Waveforms and Test Circuit



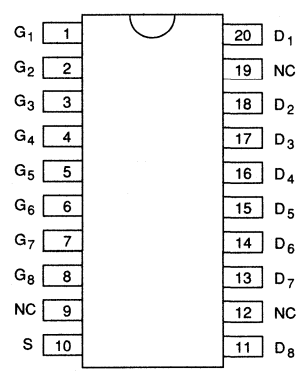


Pin Configuration and Schematic



top view

18-pin DIP



top view

SOW-20

Semicustom 8 N-Channel Monolithic High Voltage Array With Logic

Ordering Information

HV_{OUT} (Max)	R_{OUT} (Max)	$I_{OUT(ON)}$ (Max)	$I_{OUT(OFF)}$* @ V_{OUT} = 100V Max	$I_{OUT(OFF)}$* @ V_{OUT} = 250V Max	Order Number†	Package Options
160V	350Ω	25mA	1nA	—	AN0516	Available in Plastic DIP, Surface Mount SOIC, and Die.
320V	350Ω	25mA	—	1nA	AN0532	

* Average current per channel, measured with all eight channels connected in parallel.
† Excluding package suffix.

Features

- ☐ Custom logic control
- ☐ Low output leakage current
- ☐ ESD Input protection
- ☐ Interfaces directly to CMOS logic
- ☐ 8 independent channels
- ☐ Low crosstalk between channels
- ☐ Low power dissipation
- ☐ Free from secondary breakdown

Applications

- ☐ High impedance/low leakage measurements for Bare Board Testers
- ☐ Sample and hold circuits
- ☐ High voltage electrostatic array drivers
- ☐ Addressable multi-channel driver array

Absolute Maximum Ratings[1]

Output Voltage, HV_{OUT}	320V†
Logic Supply Voltage, V_{DD}	-0.5V to 18V
Logic Input Voltage	-0.5V to V_{DD}+0.3V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature[2]	300°C
Channel to Channel Crosstalk	10mV/V

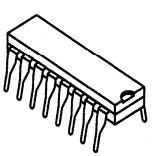
Notes:
1. All voltages referenced to V_{SS}.
2. Distance of 1.6mm from case for 10 seconds.
† For AN0532

General Description

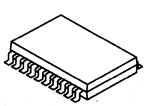
The Supertex AN05 series of semicustom High Voltage Monolithic devices consist of 8-channel open drain common source N-channel array with logic. The Logic configuration and packaging are determined by customer requirements.

The AN0516 and AN0532 are ideally suited for low leakage/high impedance measurement, providing excellent accuracy and resolution for Automatic Test Equipment.

Package Options (Note 1)



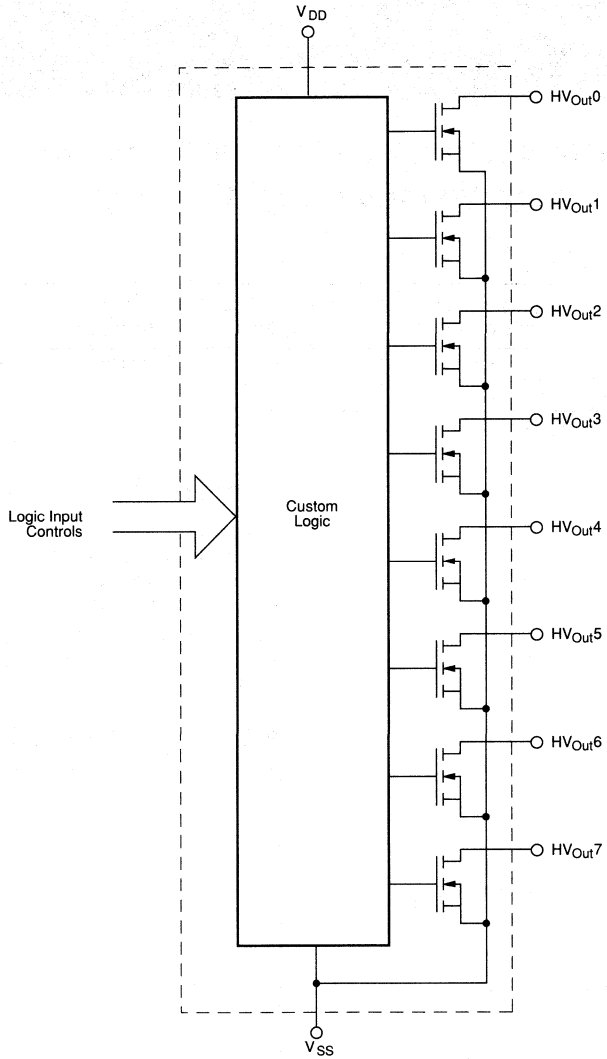
16-Lead DIP



SOW-20

Note1: Consult Factory for other package options.

Block Diagram



Pin Configuration and Package

Based on customer requirements

8 Channel MOSFET Array
Monolithic P-Channel Enchancement Mode

Ordering Information

BV_{DSS}/ BV_{DGS} (min)	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	I_{DSS}** @ V_{DS} = -100V Max	I_{DSS}** @ V_{DS} = -250V Max	Order Number / Package		
					18-Lead Plastic DIP	Plastic SOW-20*	Die†
-160V	700Ω	-15mA	-1.5nA	—	AP0116NA	AP0116WG	AP0116ND
-200V	600Ω	-15mA	—	—	AP0120NA	—	AP0120ND
-300V	600Ω	-15mA	—	—	AP0130NA	—	AP0130ND
-320V	700Ω	-15mA	—	-1.5nA	AP0132NA	AP0132WG	AP0132ND
-400V	700Ω	-15mA	—	—	AP0140NA	AP0140WG	AP0140ND

* Same as SO-20 with 300 mil wide body.
** Average current per channel, measured with all eight channels connected in parallel.
† MIL visual screening available

Features

- ☐ Low drain to source leakage for AP0116 and AP0132
- ☐ 160-volt to 400-volt capability
- ☐ Interfaces directly to CMOS logic
- ☐ 8 independent channels
- ☐ Low crosstalk between channels
- ☐ Low power dissipation
- ☐ Pin compatible with industry standard driver array
- ☐ Free from Secondary breakdown

Applications

- ☐ High voltage electroluminescent panel drivers
- ☐ High voltage electrostatic array drivers
- ☐ General multi-channel driver array

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C
Channel-to-Channel Crosstalk	10mV/V

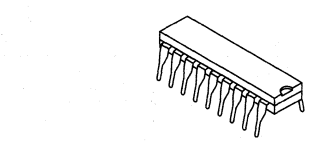
* Distance of 1.6 mm from case for 10 seconds.

General Description

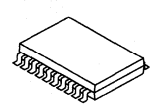
The Supertex AP01 series of high voltage arrays is designed to provide the interface between MOS logic and loads requiring high voltages and intermediate currents. Each circuit consists of eight channels in a common-source configuration with open drains. This design minimizes the number of package leads needed.

The AP0116 and AP0132 are ideally suited for low leakage/high impedance measurement, providing excellent accuracy and resolution for Automatic Test Equipment.

Package Options



18-Lead DIP



SOW-20

Thermal Characteristics

Package	I_D (continuous)*	I_D (pulsed)*	Power Dissipation @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}	I_{DRM}*
18 lead plastic	-15mA	-40mA	1.5W	135	83	-15mA	-40mA
SOW - 20	-15mA	-40mA	1.4W	110	—	-15mA	-40mA

* I_D (continuous) is limited by max rated T_j.

Electrical Characteristics (@ 25°C unless otherwise specified)

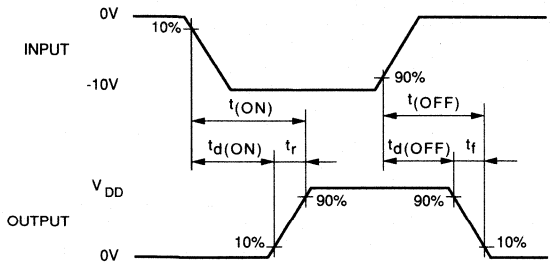
(Notes 1,2 and 3)

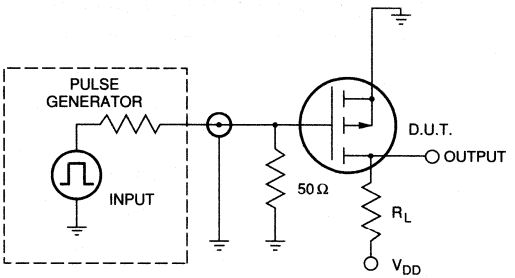
Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	AP0116	-160			V	V_{GS} = 0, I_D = -100μA
		AP0120	-200				
		AP0130	-300				
		AP132	-320				
		AP0140	-400				
$V_{GS(th)}$	Gate Threshold Voltage		-2		-5	V	V_{GS} = V_{DS}, I_D = -1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.5		mV/°C	V_{GS} = V_{DS}, I_D = -1mA
I_{GSS}	Gate Body Leakage	AP0120					
		AP0130			-10	nA	V_{GS} = ±20V, V_{DS} = 0
		AP0140					
		AP0116			-1	nA	V_{GS} = ±20V, V_{DS} = 0
		AP0132					
I_{DSS}	Zero Gate Voltage Drain Current	AP0120			-1	μA	V_{GS} = 0, V_{DS} = Max Rating(3)
		AP0130			-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating
		AP0140					T_A = 125°C(3)
		AP0116			-1	nA	V_{GS} = ±20V, V_{DS} = -100V(3)
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C(3)
		AP0132			-1.5	nA	V_{GS} = ±20V, V_{DS} = -250V(3)
					-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C(3)
$I_{D(ON)}$	ON-State Drain Current		-15			mA	V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	AP0120			600	Ω	V_{GS}= -10V, I_D = -10mA
		AP0130					
		AP0116			700	Ω	V_{GS}= -10V, I_D = -10mA
		AP0132					
		AP0140					
$\Delta R_{DS(th)}$	Change in $R_{DS(th)}$ with Temperature			0.8		%/°C	V_{GS} = -10V, I_D = -10mA,
G_{FS}	Forward Transconductance		3.0	5.0		m℧	V_{DS} = -25V, I_D = -5mA
C_{ISS}	Input Capacitance			5.0	7.5	pF	V_{GS} = 0, V_{DS} = -25V, f = 1MHz
C_{OSS}	Common Source Output Capacitance			3.0	5.0		
C_{RSS}	Reverse Transfer Capacitance			1.0	2.0		
$t_{d(ON)}$	Turn-ON Delay Time			3		ns	V_{DS} = -25V, I_D = -10mA R_S = 50Ω, $V_{GS(ON)}$ = -10V
t_r	Rise Time			3			
$t_{d(OFF)}$	Turn-OFF Delay Time			5			
t_f	Fall Time			3			
V_{SD}	Diode Forward Voltage Drop				-1.5	V	V_{GS} = 0, I_{SD} = -25mA

Notes:

1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.
3. Average current per channel, measured with all 8 channels connected in parallel.

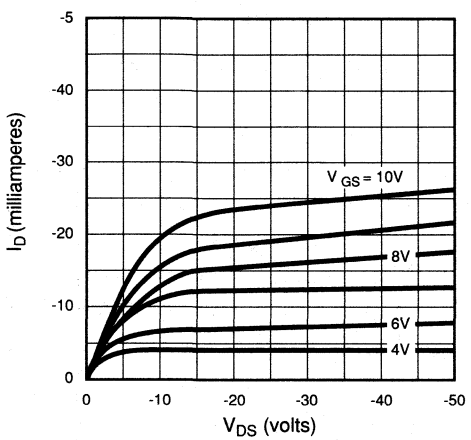
Switching Waveforms and Test Circuit



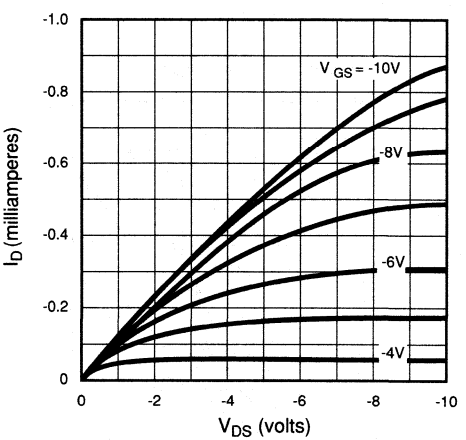


Typical Performance Curves

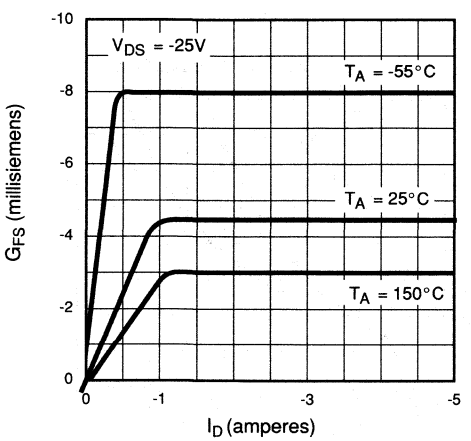
Output Characteristics



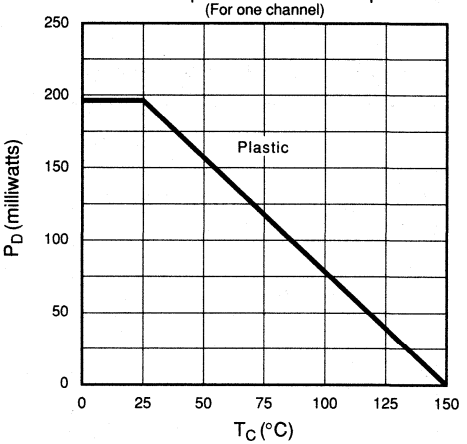
Saturation Characteristics



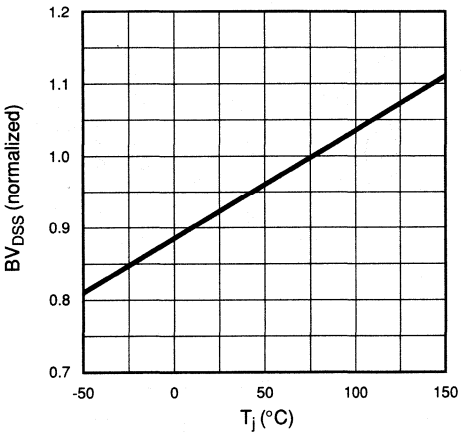
Transconductance vs. Drain Current



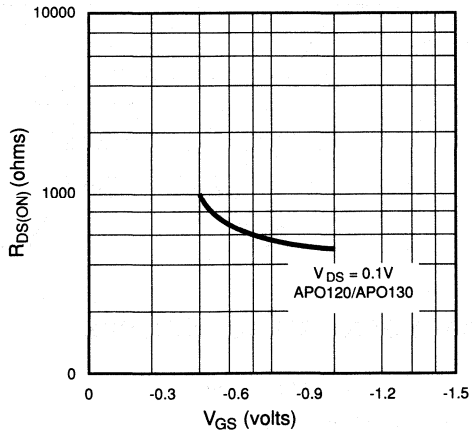
Power Dissipation vs. Case Temperature
(For one channel)



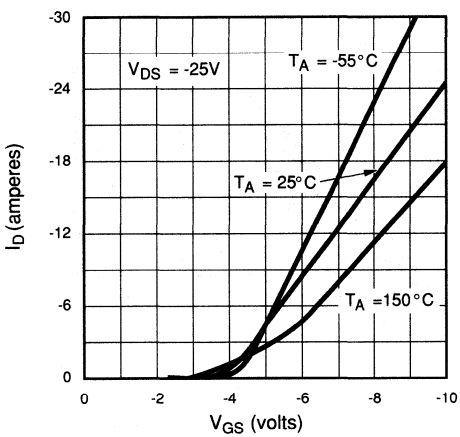
BV_{DSS} Variation with Temperature



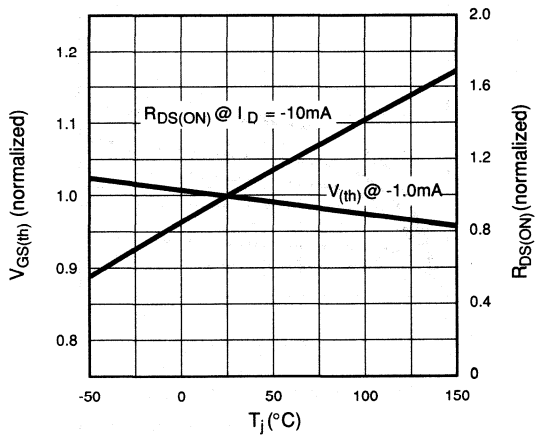
On-Resistance vs. Gate-to-Source Voltage



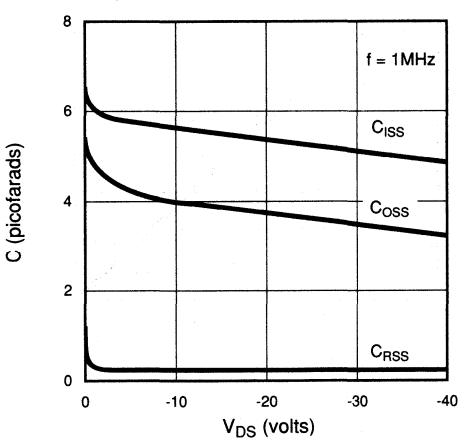
Transfer Characteristics



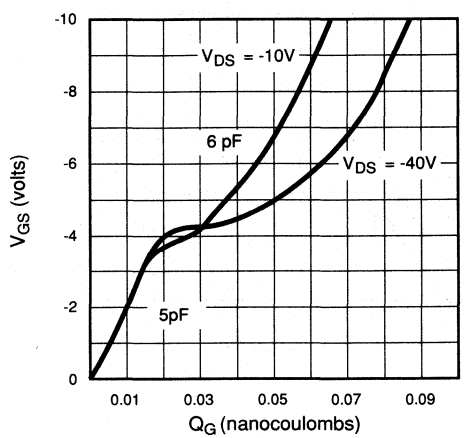
$V_{(th)}$ and R_{DS} Variation with Temperature



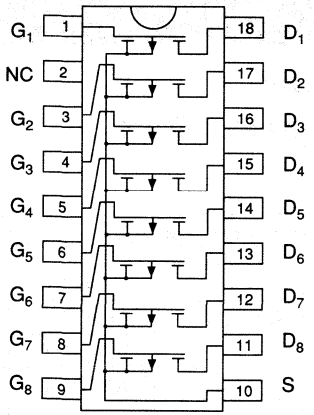
Capacitance vs. Drain-to-Source Voltage



Gate Drive Dynamic Characteristics

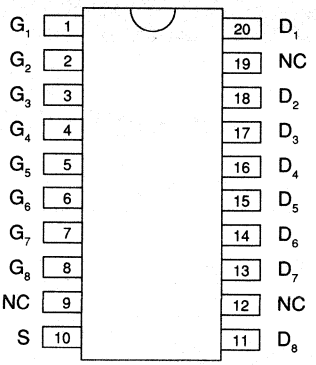


Pin Configuration and Schematic



top view

18-pin DIP



top view

SOW-20

8 Channel MOSFET Array
Monolithic P-Channel Enchancement Mode

Ordering Information

BV_{DSS}/ BV_{DGS} (min)	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	I_{DSS}** @ V_{DS} = -100V Max	I_{DSS}** @ V_{DS} = -250V Max	Order Number / Package		
					18-Lead Plastic DIP	Plastic SOW-20*	Die†
-160V	700Ω	-15mA	-1.5nA	—	AP0416NA	AP0416WG	AP0416ND
-200V	600Ω	-15mA	—	—	AP0420NA	—	AP0420ND
-300V	600Ω	-15mA	—	—	AP0430NA	—	AP0430ND
-320V	700Ω	-15mA	—	-1.5nA	AP0432NA	AP0432WG	AP0432ND
-400V	700Ω	-15mA	—	—	AP0440NA	AP0440WG	AP0440ND

* Same as SO-20 with 300 mil wide body.
** Average current per channel, measured with all eight channels connected in parallel.
† MIL visual screening available

Features

- ☐ ESD Gate Protection
- ☐ Low drain to source leakage for AP0416 and AP0432
- ☐ 160-volt to 400-volt capability
- ☐ Interfaces directly to CMOS logic
- ☐ 8 independent channels
- ☐ Low crosstalk between channels
- ☐ Low power dissipation
- ☐ Pin compatible with industry standard driver array
- ☐ Free from Secondary breakdown

Applications

- ☐ High impedance/low leakage measurements for Bare Board Testers
- ☐ High voltage electroluminescent panel drivers
- ☐ High voltage electrostatic array drivers
- ☐ General multi-channel driver array

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C
Channel-to-Channel Crosstalk	10mV/V

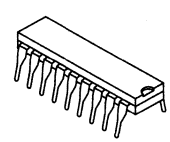
* Distance of 1.6 mm from case for 10 seconds.

General Description

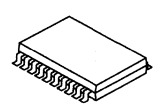
The Supertex AP04 series of high voltage arrays is a ruggedized ESD gate protected version of the Supertex AP01 series. These multichannel arrays meet the EIA ESD standard of 2000V, 100pF capacitor in series with a 1.5KΩ resistor. They are designed to provide the interface between MOS logic and loads requiring high voltages and intermediate currents. Each circuit consists of eight channels in a common-source configuration with open drains. This design minimizes the number of package leads needed.

The AP0416 and AP0432 are ideally suited for low leakage/high impedance measurement, providing excellent accuracy and resolution for Automatic Test Equipment.

Package Options



18-Lead DIP



SOW-20

Thermal Characteristics

Package	I_D(continuous)*	I_D(pulsed)*	Power Dissipation @T_C=25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}	I_{DRM}*
18 lead plastic	-15mA	-40mA	1.5W	135	83	-15mA	-40mA
SOW -20	-15mA	-40mA	1.4W	110	—	-15mA	-40mA

* I_D (continuous) is limited by max rated T_j

Electrical Characteristics (@ 25°C unless otherwise specified)

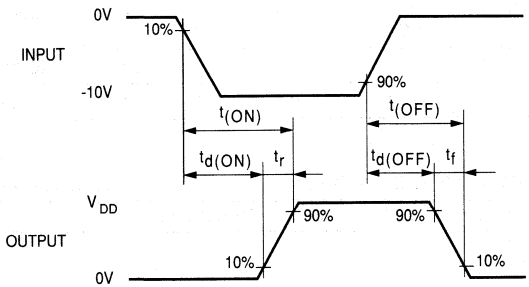
(Notes 1, 2 and 3)

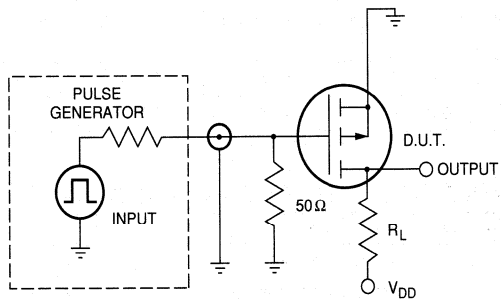
Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	AP0416	-160			V	I_D = -100μA, V_{GS}= 0V
		AP0420	-200				
		AP0430	-300				
		AP0432	-320				
		AP0440	-400				
$V_{GS(th)}$	Gate Threshold Voltage		-2		-5	V	V_{GS} = V_{DS}, I_D = -1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.5		mV/°C	V_{GS} = V_{DS}, I_D = -1mA
I_{GSS}	Gate Body Leakage	AP0420			-10	nA	V_{GS} = ±20V, V_{DS} =0V (3)
		AP0430					
		AP0440					
		AP0416			-1	nA	V_{GS} = ±20V, V_{DS} =0V (3)
		AP0432					
I_{DSS}	Zero Gate Voltage Drain Current	AP0420			-1	μA	V_{GS} = 0, V_{DS} = Max Rating (3)
		AP0430			-1	mA	V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A =125°C (3)
		AP0440					
		AP0416			-1.5	nA	V_{GS} = 0V, V_{DS} = -100V (3)
					-1	mA	V_{GS} = 0V, V_{DS} = 0.8 Max Rating T_A=125°C (3)
		AP0432			-1.5	nA	V_{GS} = 0V, V_{DS} = -250V (3)
					-1	mA	V_{GS} = 0V, V_{DS} = 0.8 Max Rating T_A = 125°C (3)
$I_{D(ON)}$	ON-State Drain Current		-15			mA	V_{GS} = -10V, V_{DS} = -25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance	AP0420			600	Ω	V_{GS} = -10V, I_D = -10mA
		AP0430					
		AP0416			700	Ω	V_{GS} = -10V, I_D = -10mA
		AP0432					
		AP0440					
$\Delta R_{DS(ON)}$	Charge in $R_{DS(ON)}$ with Temperature			0.8		%/°C	V_{GS} = -10V, I_D = -10mA
G_{FS}	Forward Transconductance		3.0	5.0		m℧	V_{DS} = -25V, I_D = -5mA
C_{ISS}	Input Capacitance			8.0	12.0	pF	V_{DS} = -25V, V_{GS} = 0V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			5.0	8.0		
C_{RSS}	Reverse Transfer Capacitance			1.6	3.2		
$t_{d(ON)}$	Turn-ON Delay Time			5.0		ns	V_{DS} = -25V, I_D = -10mA, R_S = 50Ω, $V_{GS(ON)}$ = -10V
t_r	Rise Time			5.0			
$t_{d(OFF)}$	Turn-OFF Delay Time			8.0			
t_f	Fall Time			5.0			
V_{SD}	Diode Forward Voltage Drop				-1.5	V	V_{GS} = 0V, I_{SD} = -25mA

Notes:

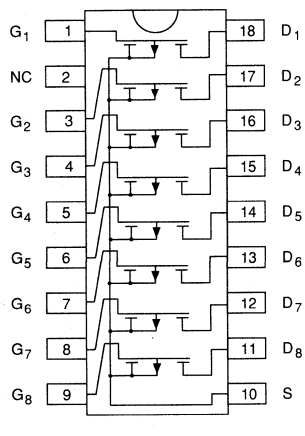
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300mS pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.
3. Average current per channel, measured with all 8 channels connected in parallel.

Switching Waveforms and Test Circuit



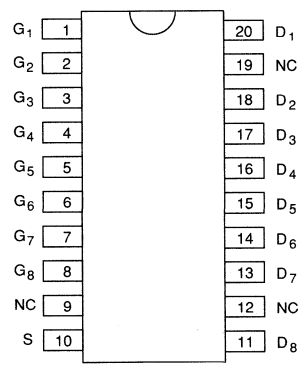


Pin Configuration and Schematic



top view

18-pin DIP



top view

SOW-20

Semicustom 8 P-Channel Monolithic High Voltage Array With Logic

Ordering Information

HV_{OUT} (Max)	R_{OUT} (Max)	$I_{OUT(ON)}$ (Max)	$I_{OUT(OFF)}$* @ V_{OUT} = 100V Max	$I_{OUT(OFF)}$* @ V_{OUT} = 250V Max	Order Number†	Package Options
-160V	700Ω	-15mA	-1.5nA	—	AP0516	Available in Plastic DIP, Surface Mount SOIC, and Die.
-320V	700Ω	-15mA	—	-1.5nA	AP0532	

* Average current per channel, measured with all eight channels connected in parallel.
† Excluding package suffix.

Features

- ☐ Custom logic control
- ☐ Low output leakage current
- ☐ ESD Input protection
- ☐ Interfaces directly to CMOS logic
- ☐ 8 independent channels
- ☐ Low crosstalk between channels
- ☐ Low power dissipation
- ☐ Free from scecondary breakdown

Applications

- ☐ High impedance/low leakage measurements for Bare Board Testers
- ☐ Sample and hold circuits
- ☐ High voltage electrostatic array drivers
- ☐ Addressable multi-channel driver array

Absolute Maximum Ratings[1]

Output Voltage, HV_{OUT}	-320V†
Logic Supply Voltage, V_{DD}	+0.5V to -18V
Logic Input Voltage	+0.5V to V_{DD}-0.3V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature [2]	300°C
Channel to Channel Crosstalk	10mV/V

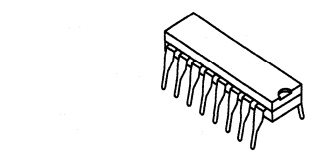
Notes:
1. All voltages referenced to V_{SS}.
2. Distance of 1.6mm from case for 10 seconds.
† For AN0532

General Description

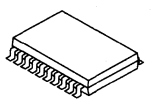
The Supertex AP05 series of semicustom High Voltage Monolithic devices consist of 8-channel open drain common source P-channel array with logic. The Logic configuration and packaging are determined by customer requirements.

The AP0516 and AP0532 are ideally suited for low leakage/high impedance measurement, providing excellent accuracy and resolution for Automatic Test Equipment.

Package Options (Note 1)



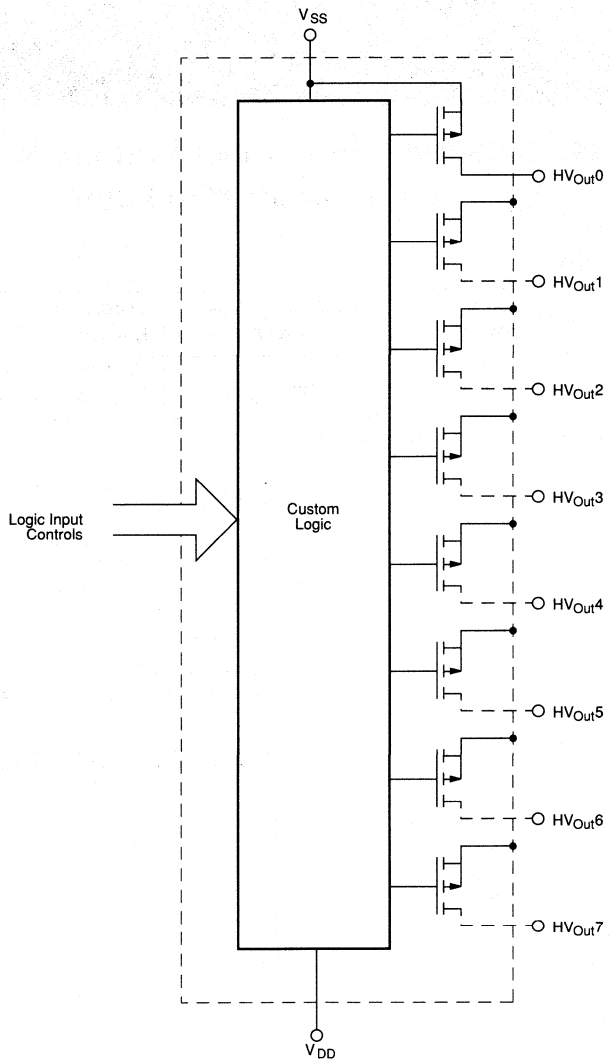
16-Lead DIP



SOW-20

Note1: Consult Factory for other package options.

Block Diagram



Pin Configuration and Package

Based on customer requirements

8-Channel Logic To High-Voltage Level Translator

Ordering Information

Device	Package Options			
	20 Lead C-DIP†	20 Lead Plastic DIP	Plastic SOW-20*	Die
HT01	HT0130C	HT0130P	HT0130WG	HT0130X

* Same as SO-20 300 mil wide body.
† Side brazed dual in-line package.

Features

- ☐ Operating voltage up to 300V
- ☐ 5V to 15V logic input capability
- ☐ Output swings below GND if required
- ☐ Drives high-voltage P-Channel MOS from logic level signal
- ☐ Surface mount packaging available
- ☐ No "floating logic" required
- ☐ 8 independent channels

Applications

- ☐ ATE systems
- ☐ Printers/plotters
- ☐ P-Channel MOSFET control

Absolute Maximum Ratings [1,2]

Supply voltage, V_{DD}		V_{NN} - 0.3V to +16V
Supply Voltage, V_{PP}		V_{NN} - 0.3V to + 300V
Supply Voltage, V_{NN}		-16V to 0.3V
Logic inputs levels	V_{IN}	V_{NN} - 0.3V to V_{DD} + 0.3V
	V_{OUTPUT}	V_{PP} + 0.3V max
I_{OUT} — DC per Channel		30mA
Continuous total power dissipation[2]		700mW
Operating temperature range		0°C to 70°C
Storage temperature range		-65°C to + 150°C

Notes:
1: All voltages are referenced to chip ground.
2: For operation above 25°C ambient derate lineraly to 85°C at 8mW/°C.

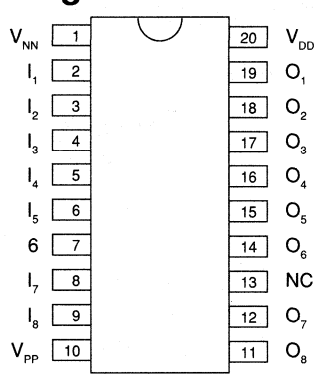
General Description

The Supertex HT01 8-channel Level Translator is designed to implement the necessary level translation between logic level signals and voltage swings required to drive high-voltage P-Channel MOSFET transistors. This device is intended to provide gate drive signals to devices such as the Supertex AP01 P-Channel MOSFET Array in applications requiring active pull-up to a high-voltage (V_{PP}) line of up to 300 volts. Logic input can be from 5 volts to 15 volts and is referenced to the logic supply (V_{DD}).

When an input is switched to 4.2 volts below the V_{DD} supply, the corresponding output will typically switch from V_{PP} to V_{PP} -14 volts. If the V_{PP} supply remains above 12 volts, the negative supply (V_{NN}) would be connected to system ground (GND). If variations of the V_{PP} supply level require the P-Channel MOSFET gate drive to swing below GND in order to turn on, connect the V_{NN} pin to a negative supply of up to -15 volts. The logic inputs can remain between V_{DD} and system ground (GND) and still provide correct operation.

In an OFF condition, the HT01 is a low power device. In an ON condition, each channel will dissipate power determined by the V_{PP} and V_{NN}voltage. Internal power dissipation must be considered when the application requires that more than one channel be active at one time, especially at higher V_{PP} voltage values.

Pin Configuration



top view

20-pin DIP/SOW 20

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter	Min	Typ	Max	Units	Conditions
I_{DD}	V_{DD} Supply Current			0.001	mA	All OFF
			0.6	3.50	mA	1 ch ON, no load
I_{PP}	V_{PP} Supply Current			0.001	mA	All OFF
			0.4	1.0	mA	1 ch ON, no load
I_{NN}	V_{NN} Supply Current			0.001	mA	All OFF
			1.0	4.50	mA	1 ch ON, no load
I_{SOURCE}	Output current	135	200		µA	Capacitive load
I_{SINK}	Output current	66	100		µA	Capacitive load
V_{ON}	Output voltage	V_{PP} - 17		V_{PP} - 10	V	V_{DD} = 4.75V
		V_{PP} - 17		V_{PP} - 12.5	V	V_{DD} = 15V
V_{OFF}	Output voltage	V_{PP} - 0.5			V	
V_Z	Zener voltage	11	14	17	V	Output to V_{PP}

AC Characteristics

Symbol	Parameter	Min	Typ	Max	Units	Conditions
t_{ON}	Turn on time, any channel		5		µs	V_{DD} = 10V, V_{NN} = GND
Δt_{ON}	Variation in t_{ON}, any 2 channels		5		%	V_{DD} = 10V, V_{NN} = GND
t_{OFF}	Turn off time, any channel		3		µs	V_{DD} = 10V, V_{NN} = GND
Δt_{OFF}	Variation in t_{OFF}, any 2 channels		5		%	V_{DD} = 10V, V_{NN} = GND

Recommended Operating Conditions*

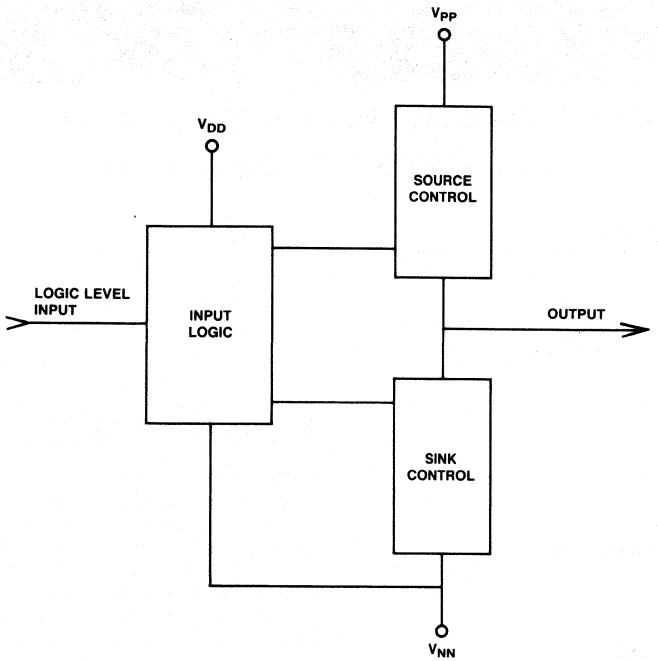
Symbol	Parameter	Min	Typ	Max	Units
V_{DD}	Logic supply voltage	4.75		15	V
V_{PP}	Positive high voltage supply	V_{NN} + 12		275	V
V_{NN}	Negative supply	-15		0	V
V_{IH}	High-level input voltage	V_{DD} - 1.2		V_{DD}	V
V_{IL}	Low-level input voltage	0		V_{DD} - 4.2	V
T_A	Operating free-air temperature	0		+70	°C

* Power-up sequence V_{NN}, V_{DD}, V_{PP}.
Power-down sequence V_{PP}, V_{DD}, V_{NN}.

Function Table

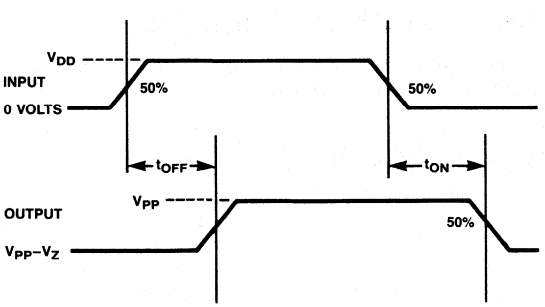
Input Condition	Output Stage
High level	V_{PP}
Low level	V_{PP} - V_Z

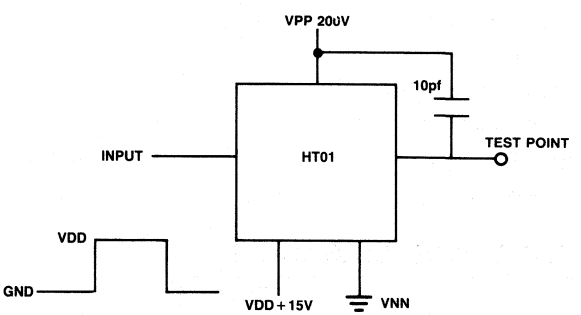
Functional Block Diagram



(One of eight channels within the HT01)

Switching Waveforms and Test Circuit





(One of eight channels within the HT01)

Complementary Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS\ (ON)}$ Max $Q_1 + Q_2$ or $Q_3 + Q_4$	Order Number / Package SOW-20*
40V	3.0Ω	TC0604WG

* Same as SO-20 with 300 mil wide body.

Features

- ☐ 4 independent channels
- ☐ 4 electrically isolated die
- ☐ Commercial and Military versions available
- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Low C_{ISS} and fast switching speeds
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Telecom Switches
- ☐ Logic level interface
- ☐ Battery operated system
- ☐ Photo voltaic drive
- ☐ Soild state relays
- ☐ Motor control

Thermal Characteristics

Package		Plastic SOW-20
I_D continuous & I_{DR} (single die)	N-Channel	1.0A
	P-Channel	-0.6A
I_D pulsed+ & I_{DRM}+	N-Channel	4.0A
	P-Channel	-2.0A
Power Dissipation @ T_C = 25°C‡		1.5W
θ_{ja} (°C/W)		85
θ_{jc} (°C/W)		—

\+ Pulse test 300 µS pulse, 2% duty cycle.
‡ Total for package.

Advanced DMOS Technology

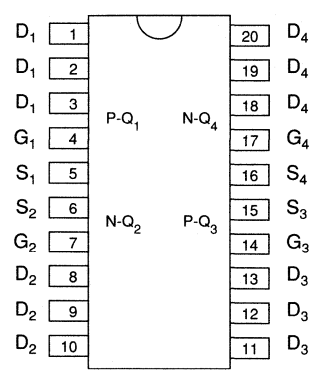
These enhancement-mode (normally-off) DMOS powerFet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Quad Arrays use four independent DMOS transistors. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Electrical Characteristics

Refer to TN06L and TP06L Data Sheets for detailed characteristics of N- and P-channel devices.

Pin Configuration



top view
SOW-20

N-Channel Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ Max	Order Number / Package
		SOW-20*
40V	1.0Ω	TN0604WG

*Same as SO-20 with 300 mil wide body.

Features

- ☐ 4 independent channels
- ☐ 4 electrically isolated die
- ☐ Commercial and Military versions available
- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Low C_{ISS} and fast switching speeds
- ☐ High input impedance and high gain

Applications

- ☐ Telecom Switches
- ☐ Logic level interface
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Soild state relays
- ☐ Motor control

Thermal Characteristics

Package	Plastic SOW-20
I_D continuous & I_{DR} (single die)	1.0A
I_D pulsed+ & I_{DRM}+	4.0A
Power Dissipation @ T_C = 25°C‡	1.5W
θ_{ja} (°C/W)	85
θ_{jc} (°C/W)	—

+ Pulse test 300 μS pulse, 2% duty cycle.
‡ Total for package.

Advanced DMOS Technology

These enhancement-mode (normally-off) DMOS power Fet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

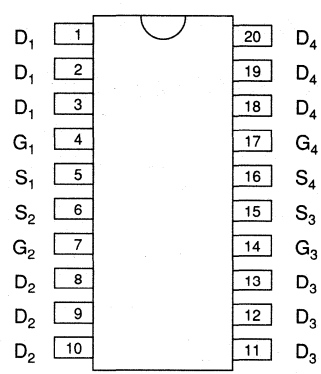
Supertex Quad Arrays use four independent DMOS transistors. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Electrical Characteristics

10

Refer to TN06L Data Sheet for detailed characteristics.

Pin Configuration



top view

SOW-20

N-Channel Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	Order Number / Package	
		14-Pin P-Dip	14-Pin C-Dip*
60V	1.5Ω	TN0606N6	TN0606N7

* 14 pin side brazed ceramic DIP

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ 4 independent channels
- ☐ 4 electrically isolated die
- ☐ Commercial and Military versions available
- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Low C_{ISS} and fast switching speeds
- ☐ High input impedance and high gain

Applications

- ☐ Telecom Switches
- ☐ Logic level interface
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Soild state relays
- ☐ Motor control

Thermal Characteristics

Package	Plastic DIP	Ceramic DIP
I_D continuous & I_{DR} (single die)	1.4A	1.60A
I_D pulsed+ & I_{DRM}+	6.0A	6.0A
Power Dissipation @ T_C = 25°C‡	3W	4W
θ_{ja} (°C/W)	83.3	62.5
θ_{jc} (°C/W)	41.6	31.2

\+ Pulse test 300 μS pulse, 2% duty cycle.
‡ Total for package.

Advanced DMOS Technology

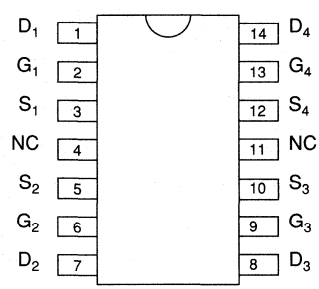
These enhancement-mode (normally-off)DMOS power Fet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Quad Arrays use four independent DMOS transistors. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Electrical Characteristics

Refer to TN06A Data Sheet for detailed characteristics.

Pin Configuration



top view

14-pin DIP

P-Channel Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS\ (ON)}$ Max	Order Number / Package
		SOW-20*
-40V	2.0Ω	TP0604WG

* Same as SO-20 with 300 mil wide body.

Features

- ☐ 4 independent channels
- ☐ 4 electrically isolated die
- ☐ Commercial and Military versions available
- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Low C_{ISS} and fast switching speeds
- ☐ High input impedance and high gain

Applications

- ☐ Telecom Switches
- ☐ Logic level interface
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Soild state relays
- ☐ Motor control

Thermal Characteristics

Package	Plastic SOW-20
I_D continuous & I_{DR} (single die)	-0.6A
I_D pulsed+ & I_{DRM}+	-2.0A
Power Dissipation @ T_C = 25°C‡	1.5W
θ_{ja} (°C/W)	85
θ_{jc} (°C/W)	—

\+ Pulse test 300 µS pulse, 2% duty cycle.
‡ Total for package.

Advanced DMOS Technology

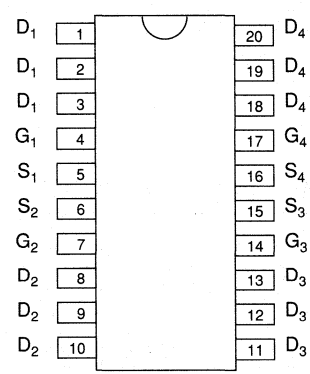
These enhancement-mode (normally-off) DMOS powerFet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Quad Arrays use four independent DMOS transistors. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Electrical Characteristics

Refer to TP06L Data Sheet for detailed characteristics.

Pin Configuration



top view

SOW 20

P-Channel Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	Order Number / Package	
		14-Pin P-Dip	14-Pin C-Dip*
-60V	3.5Ω	TP0606N6	TP0606N7

* 14 pin side brazed ceramic DIP

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ 4 independent channels
- ☐ 4 electrically isolated die
- ☐ Commercial and Military versions available
- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Low C_{ISS} and fast switching speeds
- ☐ High input impedance and high gain

Applications

- ☐ Telecom Switches
- ☐ Logic level interface
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Soild state relays
- ☐ Motor control

Thermal Characteristics

Package	Plastic DIP	Ceramic DIP
I_D continuous & I_{DR} (single die)	-0.65A	-0.75A
I_D pulsed+ & I_{DRM}+	-3.5A	-3.5A
Power Dissipation @ T_C = 25°C‡	3W	4W
θ_{ja} (°C/W)	83.3	62.5
θ_{jc} (°C/W)	41.6	31.2

\+ Pulse test 300 µS pulse, 2% duty cycle.
‡ Total for package.

Advanced DMOS Technology

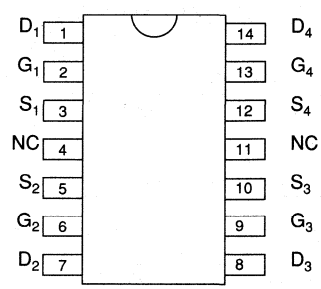
These enhancement-mode (normally-off) DMOS power Fet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Quad Arrays use four independent DMOS transisters. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Electrical Characteristics

Refer to TP06A Data Sheet for detailed characteristics.

Pin Configuration



top view

14-pin DIP

N- and P-Channel Quad Power MOSFET ARRAYS

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max) Q1 + Q2 or Q3 + Q4	$V_{GS(th)}$ (max)		Order Number / Package		
		N-Channel	P-Channel	14-Pin P-Dip	14-Pin C-Dip*	20 Terminal LCC Quad
40V	3Ω	2.0V	-3.0V	VQ3001N6	VQ3001N7	VQ3001NF
40V	3Ω	1.6V	-2.4V	TQ3001N6	TQ3001N7	TQ3001NF
20V	3Ω	2.0V	-3.0V	VQ7254N6	VQ7254N7	—

* 14 pin side brazed ceramic DIP

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices
- ☐ Low Threshold version available

Applications

- ☐ Telecom Switches
- ☐ Logic level interface
- ☐ Battery operated systems
- ☐ Photo voltaic drive
- ☐ Soild state relays
- ☐ Motor control

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 20V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) DMOS power Fet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Quad Arrays use four independent DMOS transistors. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Thermal Characteristics

Package	I_D (continuous)*		I_D (pulsed)†		Power Dissipation*	θ_{ja}	θ_{jc}	I_{DR}		I_{DRM}†	
	N	P	N	P	@ T_C = 25°C	°C/W	°C/W	N	P	N	P
Ceramic Dip	850mA	-600mA	3.0A	3.0A	2.0W	—	62.5	850mA	-600mA	3.0A	-3.0A
Plastic Dip	640mA	-450mA	3.0A	3.0A	1.5W	—	83.3	640mA	-450mA	3.0A	-3.0A
20 Terminal LCC	410mA	-300mA	3.0A	3.0A	1.0W	—	125.0	410mA	-300mA	3.0A	-3.0A

* Total for 4 die.
† Each die.

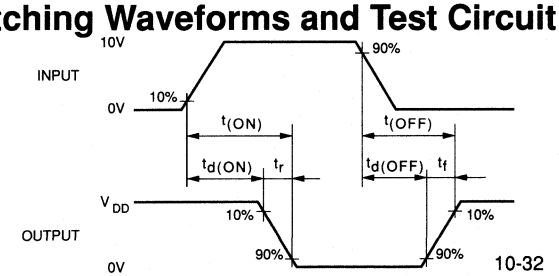
Electrical Characteristics (@ 25°C unless otherwise specified)

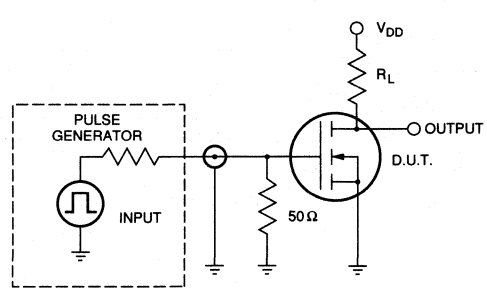
(Notes 1, 2, and 3)

Symbol	Parameter		N-Channel Min	N-Channel Max	P-Channel Min	P-Channel Max	Unit	Test Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	TQ3001	40		-40		V	V_{GS} = 0, I_D = 10µA
		VQ3001						
		VQ7254	20		-20			
$V_{GS(th)}$	Gate Threshold Voltage	VQ3001	0.8	2.0	-0.8	-3.0	V	V_{GS} = V_{DS}, I_D = 1mA, T_A = 25°C
		VQ7254						
		TQ3001	0.6	1.6	-1.0	-2.4	V	
		VQ3001	0.5		-0.65		V	V_{GS} = V_{DS}, I_D = 1mA, T_A = 85°C
		VQ7254						
I_{GSS}	Gate Body Leakage			100		-100	nA	V_{GS} =16V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			0.5		-0.5	µA	V_{GS} = 0, V_{DS} = 0.8 Min Rating
$V_{DS\ (ON)}$	Total Static Drain-to-Source ON-State voltage	VQ3001		1.0		-2.0	V	V_{GS} = 11.4V, I_D = 1A
		TQ3001						
		VQ7254		1.0		-2.0		
$R_{DS\ (ON)}$	Total Static Drain-to-Source ON-State Resistance	TQ3001		1.5		3.5	Ω	V_{GS} = 5.0V, I_D = 250mA
		VQ3001		1.0		2.0		V_{GS} = 11.4V, I_D = 1A
		TQ3001						
		VQ7254		1.0		2.0		
G_{FS}	Forward Transconductance		200		200		mʊ	$V_{DS} \geq 2V_{DS(ON)}$, I_D = 0.5A
C_{ISS}	Input Capacitance			190		195	pF	V_{GS} = 0, V_{DS} = 25v f = 1Mz
C_{OSS}	Output Capacitance			110		120		
C_{RSS}	Reverse Transfer Capacitance			50		60		
$t_{d(ON)}$	Turn-ON Delay Time			30		30	ns	V_{DD} = 17V, R_S = 50Ω
$t_{d(OFF)}$	Turn-OFF Delay Time			30		30	ns	R_L = 15Ω
V_{SD}	Forward ON Voltage	VQ7254		-0.75		0.75	V	V_{GS} = 0, I_F = 50mA
		VQ3001		-1.20		1.2		V_{GS} = 0, I_F = 1A
		TQ3001						

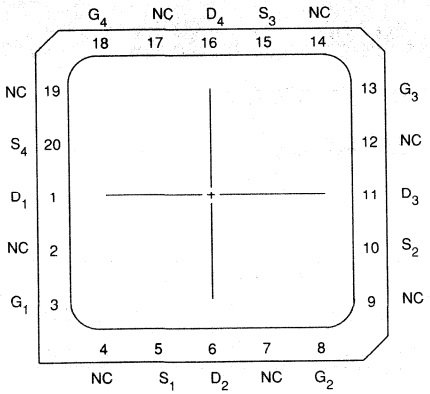
Notes:
1. All D.C. parameters 100% tested (pulse test: 300µs pulse, 2% duty cycle).
2. All A.C. parameters sample tested.
3. Refer to device types TN06L and TP06L for characteristic curves.

Switching Waveforms and Test Circuit



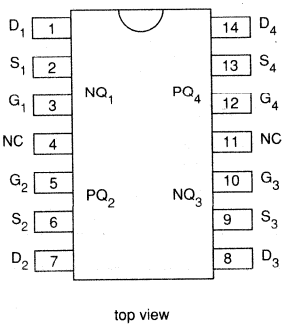


Pin Configuration and Schematic



top view

20-pin Ceramic LCC



top view

14-pin DIP

10

Complementary Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max) Q1 + Q2 or Q3 + Q4	Order Number / Package	
		14-Pin P-Dip	14-Pin C-Dip*
60V	11Ω	VC0106N6	VC0106N7

* 14-pin Side Brazed Ceramic Dip.

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ 4 independent channels
- ☐ 4 electrically isolated die
- ☐ Commercial and Military versions available
- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Low C_{ISS} and fast switching speeds
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Amplifiers
- ☐ Convertors
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Thermal Characteristics

Package		Plastic DIP	Ceramic DIP
I_D continuous & I_{DR} (single die)	N-Channel	0.56A	0.7A
	P-Channel	-0.35A	-0.4A
I_D pulsed+ & I_{DRM}+	N-Channel	2.0A	2.0A
	P-Channel	-1.0A	-1.0A
Power Dissipation @ T_C = 25°C‡		2W	3W
θ_{ja} (°C/W)		110	83.3
θ_{jc} (°C/W)		62.5	41.6

+ Pulse test 300 μS pulse, 2% duty cycle.
‡ Total for package.

Advanced DMOS Technology

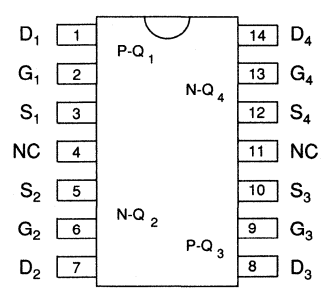
These enhancement-mode (normally-off) DMOS power Fet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Quad Arrays use four independent DMOS transistors. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Electrical Characteristics

Refer to VN01A and VP01A Data Sheets for detailed characteristics of N- and P-Channel devices.

Pin Configuration



top view

14-pin DIP

N-Channel Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	Order Number / Package	
		14-Pin P-Dip	14-Pin C-Dip*
40V	3Ω	VN0104N6	VN0104N7
60V	3Ω	VN0106N6	VN0106N7

* 14-pin Side Brazed Ceramic Dip.

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ 4 independent channels
- ☐ 4 electrically isolated die
- ☐ Commercial and Military versions available
- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Low C_{ISS} and fast switching speeds
- ☐ High input impedance and high gain

Applications

- ☐ Motor control
- ☐ Amplifiers
- ☐ Convertors
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Thermal Characteristics

Package	Plastic DIP	Ceramic DIP
I_D continuous & I_{DR} (single die)	0.56A	0.7A
I_D pulsed+ & I_{DRM}+	2.0A	2.0A
Power Dissipation @ T_C = 25°C‡	2W	3W
θ_{ja} (°C/W)	110	83.3
θ_{jc} (°C/W)	62.5	41.6

\+ Pulse test 300 µS pulse, 2% duty cycle.
‡ Total for package.

Advanced DMOS Technology

These enhancement-mode (normally-off) DMOS power Fet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

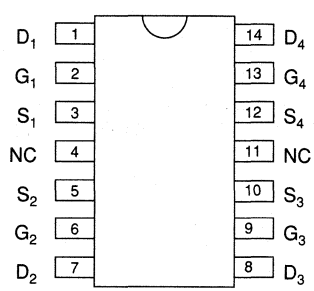
Supertex Quad Arrays use four independent DMOS transistors. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

10

Electrical Characteristics

Refer to VN01A Data Sheet for detailed characteristics.

Pin Configuration



top view

14-pin DIP

N-Channel Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	Order Number / Package	
		20 Terminal Ceramic LCC	Die†
60V	4Ω	VN2106NF	VN2106ND
100V	4Ω	VN2110NF	VN2110ND

† MIL visual screening available

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ 4 independent channels
- ☐ 4 electrically isolated die
- ☐ Commercial and Military versions available
- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Low C_{ISS} and fast switching speeds
- ☐ High input impedance and high gain

Applications

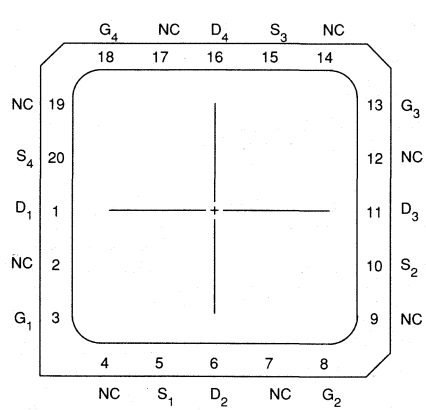
- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Advanced DMOS Technology

These enhancement-mode (normally-off) DMOS power Fet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Quad Arrays use four independent DMOS transistors. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Pin Configuration



top view

20-pin Ceramic LCC

Thermal Characteristics

Package	I_D (continuous)†	I_D (pulsed)	Power Dissipation* @ T_C = 25°C	θ_{ja} °C/W	θ_{jc} °C/W	I_{DR}	I_{DRM}
20 Terminal LCC	0.46A**	2.0A	1.25W	170	100	0.46A**	2.0A

= I_D (continuous) is limited by max rated T_j.
* Total for package.

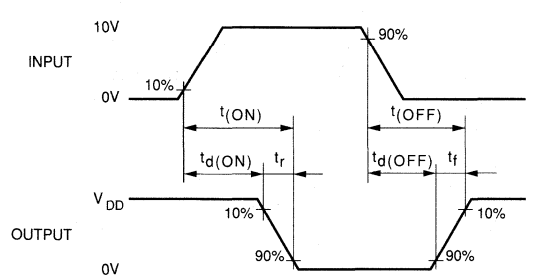
Electrical Characteristics (@ 25°C unless otherwise specified)

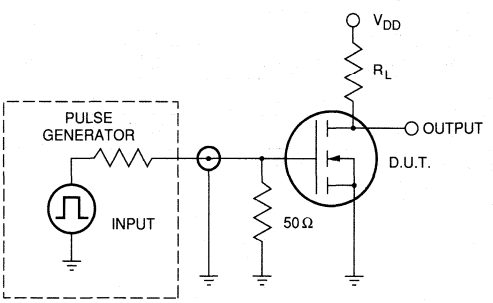
(Notes 1 and 2)

Symbol	Parameter		Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	VN2110	100			V	I_D = 1mA, V_{GS} = 0
		VN2106	60				
$V_{GS(th)}$	Gate Threshold Voltage		0.8		2.4	V	V_{GS} = V_{DS}, I_D = 1mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature			-3.8	-5.5	mV/°C	I_D = 1mA, V_{GS} = V_{DS}
I_{GSS}	Gate Body Leakage			0.1	100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current				1	µA	V_{GS} = 0, V_{DS} = Max Rating
					100		V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current		0.15	1.0		A	V_{GS} = 5V, V_{DS} = 25V
			1.0	2.50			V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			4.50	6	Ω	V_{GS} = 5V, I_D = 75mA
				2	4		V_{GS} = 10V, I_D = 500mA
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature			0.70	1.0	%/°C	I_D = 1A, V_{GS} = 10V
G_{FS}	Forward Transconductance		150	400		m℧	V_{DS} = 25V, I_D = 0.5A
C_{ISS}	Input Capacitance				50	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance				25		
C_{RSS}	Reverse Transfer Capacitance				5		
$t_{d(ON)}$	Turn-ON Delay Time			3	5	ns	V_{DD} = 25V I_D = 1.0A R_S = R_L = 50Ω
t_r	Rise Time			5	8		
$t_{d(OFF)}$	Turn-OFF Delay Time			6	9		
t_f	Fall Time			5	8		
V_{SD}	Diode Forward Voltage Drop			1.2	1.8	V	I_{SD} = 1.0A, V_{GS} = 0
t_{rr}	Reverse Recovery Time			400		ns	I_{SD} = 1.0A, V_{GS} = 0

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





P-Channel Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	Order Number / Package	
		14-Pin P-Dip	14-Pin C-Dip*
-40V	8Ω	VP0104N6	VP0104N7
-60V	8Ω	VP0106N6	VP0106N7

* 14-pin Side Brazed Ceramic Dip.

Features

- ☐ 4 independent channels
- ☐ 4 electrically isolated die
- ☐ Commercial and Military versions available
- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Low C_{ISS} and fast switching speeds
- ☐ High input impedance and high gain

Applications

- ☐ Motor control
- ☐ Amplifiers
- ☐ Convertors
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Thermal Characteristics

Package	Plastic DIP	Ceramic DIP
I_D continuous & I_{DR} (single die)	-0.35A	-0.4A
I_D pulsed+ & I_{DRM}+	-1.0A	-1.0A
Power Dissipation @ T_C = 25°C‡	2W	3W
θ_{ja} (°C/W)	110	83.3
θ_{jc} (°C/W)	62.5	41.6

\+ Pulse test 300 μS pulse, 2% duty cycle.
‡ Total for package.

Advanced DMOS Technology

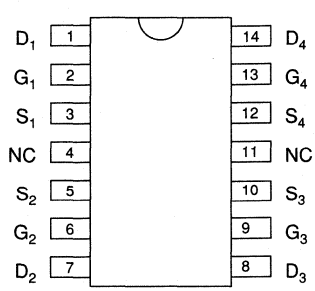
These enhancement-mode (normally-off) DMOS power Fet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Quad Arrays use four independent DMOS transistors. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Electrical Characteristics

Refer to VP01A Data Sheet for detailed characteristics.

Pin Configuration



top view

14-pin DIP

N-Channel Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
			14-Pin P-DIP	14-Pin C-DIP*
60V	5.5Ω	0.5A	VQ1000N6	VQ1000N7

* 14 pin side brazed ceramic DIP

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Very high input impedance
- ☐ Very high speed
- ☐ Low on-resistance
- ☐ No secondary breakdown
- ☐ High reliability

Applications

- ☐ Logic to high current interface
- ☐ High speed line driver
- ☐ LED digit strobe driver
- ☐ Linear amplifiers
- ☐ Stepper motor drive

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 30V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

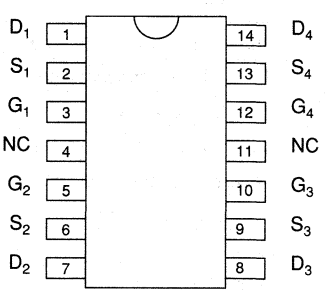
Advanced DMOS Technology

These enhancement-mode (normally-off) DMOS power Fet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Quad Arrays use four independent DMOS transistors. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

10

Pin Configuration



top view

14-pin DIP

Thermal Characteristics (@ T_A = 25°C)

Test	Unit	Each Transistor	All four Transistors
			VQ1000N7
Total Power Dissipation	Watts	1.30	2.0
Linear Derating Factor	mW/ °C	10.5	16
Thermal Resistance	°C/W	96	62.5
Thermal Coupling Factor (K) Q_1 - Q_4 or Q_2 - Q_3 Q_1 - Q_2, Q_3 - Q_4, Q_1 - Q_3 or Q_4 - Q_2	 % %	 60 50	
Continuous Drain Current [2, 3]	A	0.225	—
Pulsed Drain Current [1, 3]	A	1.0	—

Notes:
1. All D.C. parameter 100% tested at 25°C unless otherwise stated. (Pulse test: 300 µs, 2% duty cycle.)
2. I_D (continuous) is limited by max rated T_j.
3. T_C = 25°C.

Electrical Characteristics (@ 25°C unless otherwise specified)

(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	60			V	V_{GS} = 0, I_D = 100µA
$V_{GS(th)}$	Gate Threshold Voltage	0.8		2.5	V	V_{GS} = V_{DS}, I_D = 1.0mA
$\Delta V_{GS(th)}$	Change in $V_{GS(th)}$ with Temperature		-3.0	-5.0	mV/°C	V_{GS} = V_{DS}, I_D = 1.0mA
I_{GSS}	Gate Body Leakage			100	nA	V_{GS} = ±20V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			10	µA	V_{GS} = 0, V_{DS} = Max Rating
				500		V_{GS} = 0, V_{DS} = 0.8 Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	0.2			A	V_{GS} = 5V, V_{DS} = 25V
		0.5				V_{GS} = 10V, V_{DS} = 25V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			7.5	Ω	V_{GS} = 5V, I_D = 0.2A
				5.5		V_{GS} = 10V, I_D = 0.3A
$\Delta R_{DS(ON)}$	Change in $R_{DS(ON)}$ with Temperature		0.6	1.1	%/°C	V_{GS} = 10V, I_D = 0.3A
G_{FS}	Forward Transconductance	100			m℧	V_{DS} = 15V, I_D = 0.5A
C_{ISS}	Input Capacitance			60	pF	V_{GS} = 0, V_{DS} = 25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			25		
C_{RSS}	Reverse Transfer Capacitance			5		
$t_{d(ON)}$	Turn-ON Delay Time			5	ns	V_{DD} = 15V I_D = 0.6A R_S = 50Ω
t_r	Rise Time			5		
$t_{d(OFF)}$	Turn-OFF Delay Time			5		
t_f	Fall Time			5		
V_{SD}	Diode Forward Voltage Drop		-0.85		V	V_{GS} = 0, I_{SD} = 0.5A
t_{rr}	Reverse Recovery Time		165		ns	V_{GS} = 0, I_{SD} = 0.3A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Thermal Coupling and Effective Thermal Resistance

In multiple chip devices, coupling of heat between die occurs. The junction temperature can be calculated as follows:

$$\Delta T_{J1} = R_{\theta 1} P_{D1} + R_{\theta 2} K_{\theta 2} P_{D2} + R_{\theta 3} K_{\theta 3} P_{D3} + R_{\theta 4} K_{\theta 4} P_{D4} \quad (1)$$

where ΔT_{J1} is the change injunction temperature of die 1.
$R_{\theta 1}$ thru 4 is the thermal resistance of die 1 through 4.
P_{D1} thru 4 is the power dissipated in die 1 through 4.
$K_{\theta 2}$ thru 4 is the thermal coupling between die 1 and die 2 through 4.

An effective package thermal resistance can be defined as follows:

$$R_{\theta\,(EFF)} = \Delta T_{J1}/P_{DT} \quad (2)$$

where P_{DT} is the total package power dissipation.

Assuming equal thermal resistance for each die, equation (1) simplifies to:

$$\Delta T_{J1} = R_{\theta 1}(P_{D1} + K_{\theta 2} P_{D2} + K_{\theta 3} P_{D3} + K_{\theta 4} P_{D4}) \quad (3)$$

For conditions where $P_{D1} = P_{D2} = P_{D3} = P_{D4}$, $P_{DT} = 4P_D$, equation (3) can be further simplifed and, by substituting into equation (2), results in:

$$R\theta_{(EFF)} = R_{\theta 1}\,(1 + K_{\theta 2} + K_{\theta 3} + K_{\theta 4})/4 \quad (4)$$

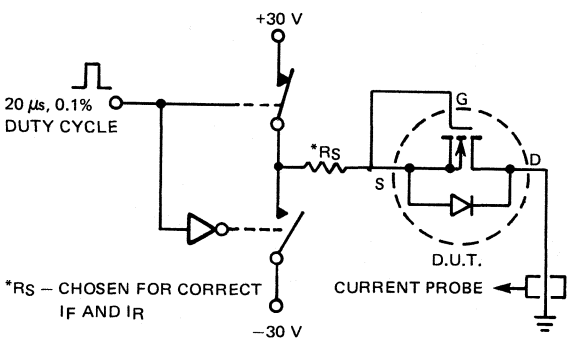
Values for the coupling factors when the ambient is used as a reference are given in the previous table. If significant power is to be dissipated in two die, die at the opposite ends of the package should be used so that lowest position junction temperatures will result.

Drain-Source Diode (t_{rr} - Reverse Recovery Time)

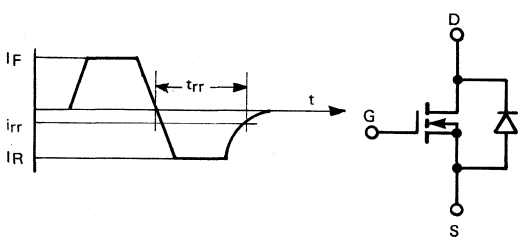
The internal drain-source diodes of DMOS Power FETs may be used as catch diodes or free-wheeling diodes. Current ratings for these diodes are the same as the contnuous and peak drain current ratings for the DMOS FET.

Reverse recovery time is measured using the circuit below. Forward and reverse current I_F and I_R are equal and are tested at the continuous and peak current ratings of the DMOS FET.

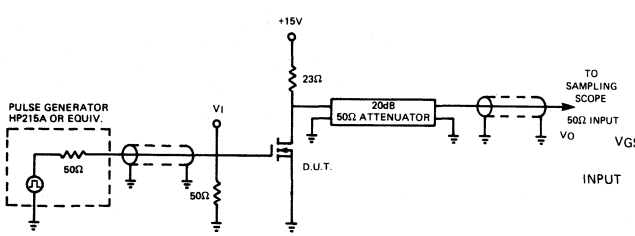
Switching Waveforms and Test Circuits



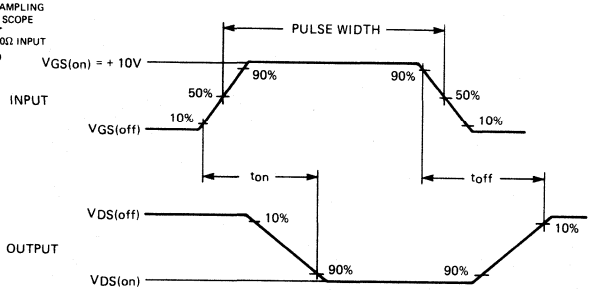
T_{RR} Test Circuit



T_{RR} Test Waveforms



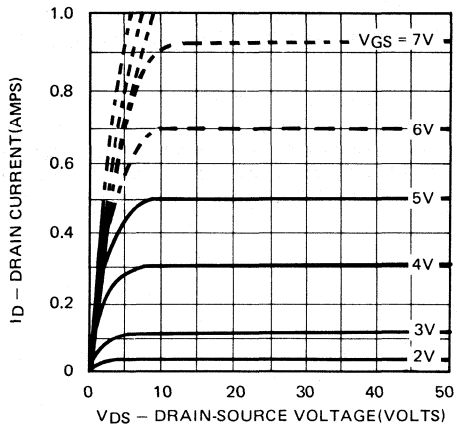
Switching Time Test Circuit



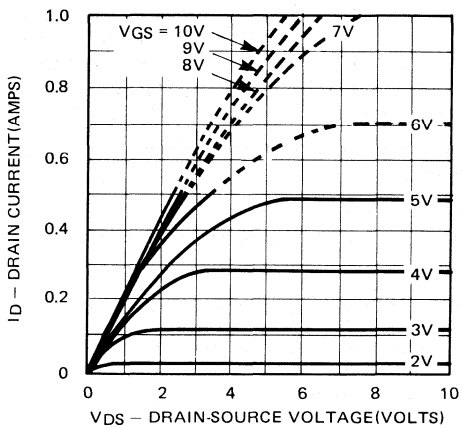
Switching Time Test Waveform

Typical Performance Curves

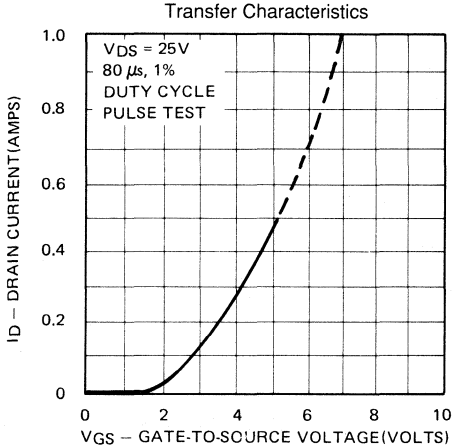
Output Characteristics



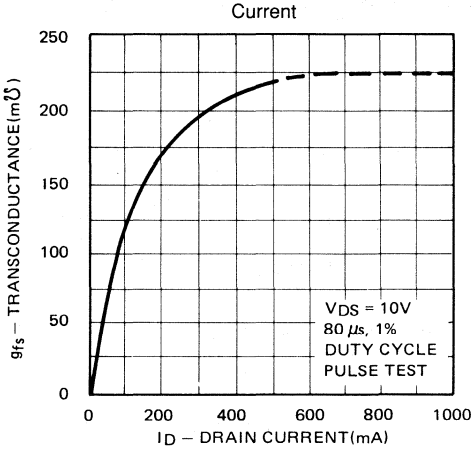
Saturation Characteristics



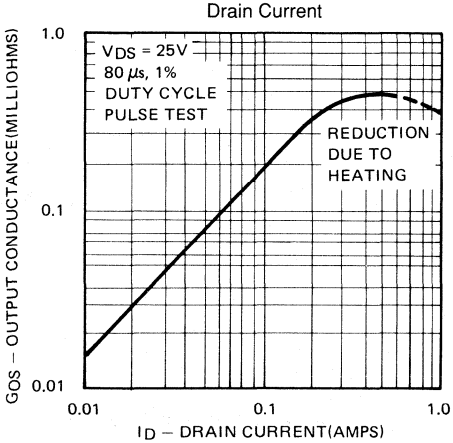
Static
Transfer Characteristics



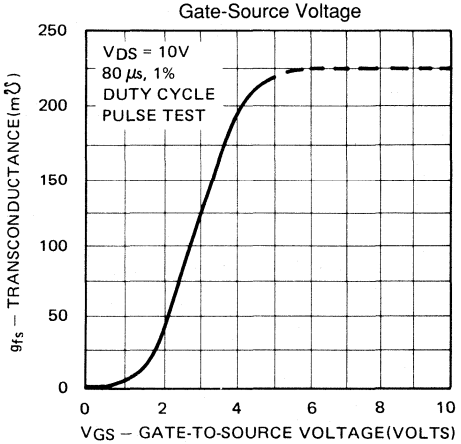
Transconductance vs Drain
Current



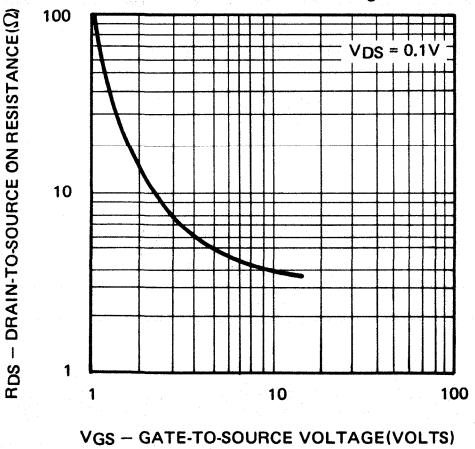
Output Conductance vs
Drain Current



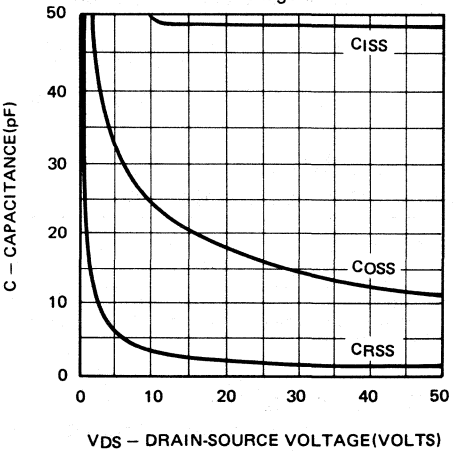
Transconductance vs
Gate-Source Voltage

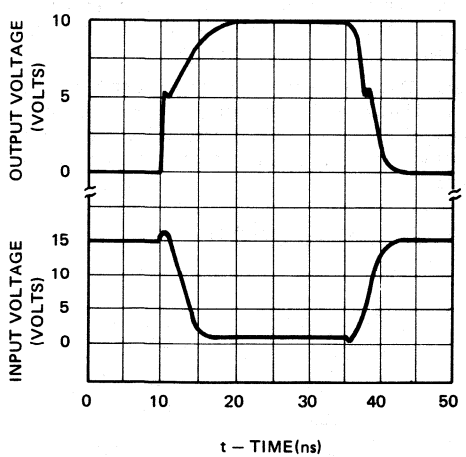


Drain-to-Source ON Resistance
vs Gate-to-Source Voltage



Capacitance vs Drain-to-Source
Voltage





Supertex inc.

N-Channel Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package
			Quad Ceramic DIP*
30V	1.0Ω	2.0A	VQ1001P

* 14 pin side brazed ceramic DIP

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

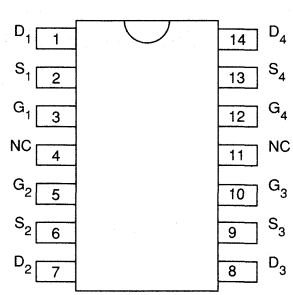
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) DMOS power Fet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Quad Arrays use four independent DMOS transistors. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Pin Configuration



top view

14-pin DIP

Thermal Characteristics

Test	Unit	Each Transistor	All Four Transistors
		VQ1001P	VQ1001P
Total Power Dissipation	Watts	1.3	2.0
Linear Derating Factor	mW/°C	10.4	9.6
Thermal Resistance	°C/W	250	104
Continuous Drain Current	A	0.85	
Pulsed Drain Current	A	3.0	

Electrical Characteristics (@ 25°C unless otherwise specified)

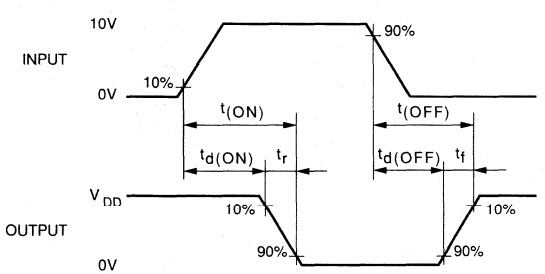
(Notes 1 and 2)

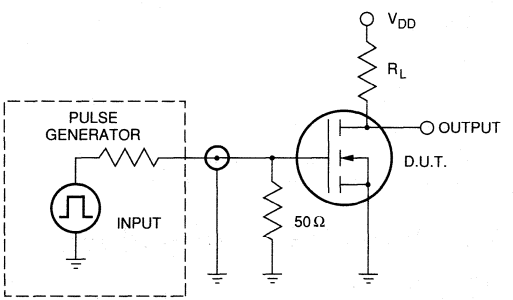
Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	30			V	V_{GS} = 0, I_D = 10μA
$V_{GS(th)}$	Gate Threshold Voltage	0.8		2.5	V	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage			100	nA	V_{GS} = ±15V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			10	μA	V_{GS} = 0, V_{DS} = Max Rating
				1		V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	2			A	V_{GS} = 12V, V_{DS} ≥ $2V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			1.75	Ω	V_{GS}= 5V, I_D = 0.2A
				1		V_{GS}= 12V, I_D = 1.0A
G_{FS}	Forward Transconductance	200			m℧	V_{DS} ≥ $2V_{DS(ON)}$, I_D = 0.5A
C_{ISS}	Input Capacitance			110	pF	V_{GS} = 0, V_{DS} = 15V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			110		
C_{RSS}	Reverse Transfer Capacitance			35		
$t_{d(ON)}$	Turn-ON Delay Time			30	ns	V_{DD} = 15V, I_D = 0.6A, R_S = 50Ω
$t_{d(OFF)}$	Turn-OFF Delay Time			30		
V_{SD}	Diode Forward Voltage Drop		0.85		V	V_{GS} = 0, I_{SD} = 1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

10

Switching Waveforms and Test Circuit





N-Channel Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

Standard Commercial Devices

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package	
			Quad Ceramic DIP*	Quad Plastic DIP
60V	3.5Ω	1.5A	VQ1004P	VQ1004J

* 14 pin side brazed ceramic DIP

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 40V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

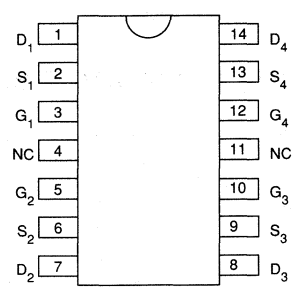
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) DMOS power Fet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Quad Arrays use four independent DMOS transistors. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Pin Configuration



top view

14-pin DIP

Thermal Characteristics

Test	Unit	Each Transistor		All Four Transistors	
		VQ1004P	VQ1004J	VQ1004P	VQ1004J
Total Power Dissipation	Watts	1.3	1.3	2.0	2.0
Linear Derating Factor	mW/°C	10.4	10.4	9.6	9.6
Thermal Resistance	°C/W	96.2	96.2	62.5	62.5
Continuous Drain Current	A	0.46	0.46		
Pulsed Drain Current	A	2.0	2.0		

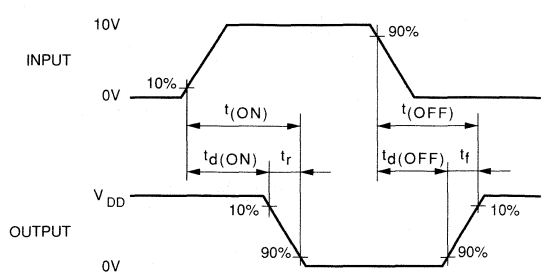
Electrical Characteristics (@ 25°C unless otherwise specified)

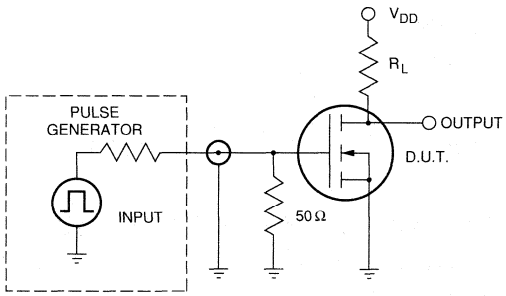
(Notes 1 and 2)

Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	60			V	V_{GS} = 0, I_D = 10μA
$V_{GS(th)}$	Gate Threshold Voltage	0.8		2.5	V	V_{GS} = V_{DS}, I_D = 1mA
I_{GSS}	Gate Body Leakage			100	nA	V_{GS} = ±15V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			1	μA	V_{GS} = 0, V_{DS} = Max Rating
				500		V_{GS} = 0, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	1.5			A	V_{GS} = 10V, V_{DS} ≥ $2V_{DS(ON)}$
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance			5	Ω	V_{GS}= 5V, I_D = 0.2A
				3.5		V_{GS}= 10V, I_D = 1.0A
G_{FS}	Forward Transconductance	170			m℧	V_{DS} ≥ $2V_{DS(ON)}$, I_D = 0.5A
C_{ISS}	Input Capacitance			60	pF	V_{GS} = 0, V_{DS} = 15V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			50		
C_{RSS}	Reverse Transfer Capacitance			10		
$t_{d(ON)}$	Turn-ON Delay Time			10	ns	V_{DD} = 15V, I_D = 0.6A, R_S = 50Ω
$t_{d(OFF)}$	Turn-OFF Delay Time			10		
V_{SD}	Diode Forward Voltage Drop		0.9		V	V_{GS} = 0, I_{SD} = 1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300ms pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

Switching Waveforms and Test Circuit





P-Channel Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package
			Quad Ceramic DIP*
-30V	2.0Ω	-1.5A	VQ2001P

* 14-pin side-brazed ceramic DIP.

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
- ☐ Ease of paralleling
- ☐ Low C_{ISS} and fast switching speeds
- ☐ Excellent thermal stability
- ☐ Integral Source-Drain diode
- ☐ High input impedance and high gain
- ☐ Complementary N- and P-Channel devices

Applications

- ☐ Motor control
- ☐ Convertors
- ☐ Amplifiers
- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 30V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

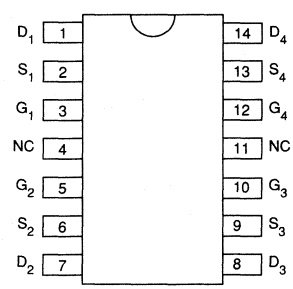
* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) DMOS power Fet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

Supertex Quad Arrays use four independent DMOS transistors. They are ideally suited to a wide range of switching and amplifying applications where high breakdown voltage, high input impedance, low input capacitance, and fast switching speeds are desired.

Pin Configuration



top view

14-pin DIP

Thermal Characteristics (T_A = 25°C)

Test	Unit	Each Transistor	All Four Transistors
Total Power Dissipation	Watts	1.3	2.0
Thermal Resistance	°C/W	96.2	62.5
Continuous Drain Current	A	-0.6	—
Pulsed Drain Current	A	-2.0	—

Electrical Characteristics (@ 25°C unless otherwise specified)

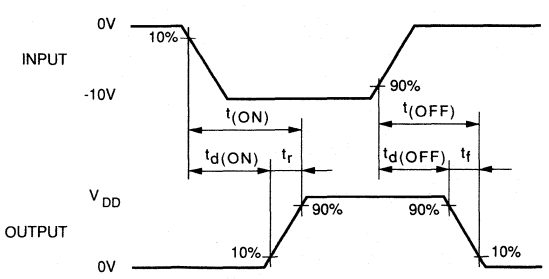
(Notes 1 and 2)

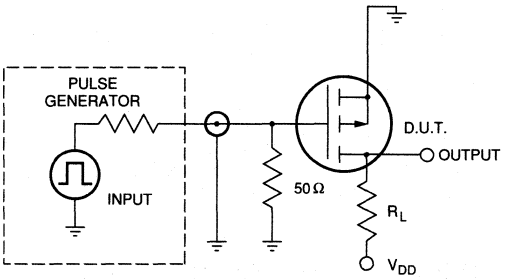
Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	-30			V	V_{GS} = 0V, V_{DS}= -10µA
$V_{GS(th)}$	Gate Threshold Voltage	-1.4	-1.8	-4.5	V	V_{GS} = V_{DS}, I_D = -1mA
I_{GSS}	Gate Body Leakage			100	nA	V_{GS} = ±15V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			-10	µA	V_{GS} = 0V, V_{DS}= Max Rating
				-500		V_{GS} = 0V, V_{DS} = 0.8 Max Rating T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	-1.5			A	V_{GS} = -12V, V_{DS} = -10V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance		1.5	2.0	Ω	V_{GS} = -12V, I_D = -1A
G_{FS}	Forward Transconductance	200			m℧	V_{DS} = -10V, I_D = -0.5A
C_{ISS}	Input Capacitance			150	pF	V_{GS} = 0, V_{DS} = -25V f = 1 MHz
C_{OSS}	Common Source Output Capacitance			120		
C_{RSS}	Reverse Transfer Capacitance			60		
$t_{d(ON)}$	Turn-ON Delay Time			30	ns	V_{DD} = -15V, I_D = -0.6A
$t_{d(OFF)}$	Turn-OFF Delay Time			30	ns	R_S = 50Ω
V_{SD}	Diode Forward Voltage Drop			1.8	V	V_{GS} = 0, I_{SD} = 1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300µs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

10

Switching Waveforms and Test Circuit





P-Channel Enhancement-Mode Vertical DMOS FET Quad Array

Ordering Information

BV_{DSS} / BV_{DGS}	$R_{DS(ON)}$ (max)	$I_{D(ON)}$ (min)	Order Number / Package
			Quad Ceramic DIP*
-90V	5.0Ω	-1.0A	VQ2006P

* 14-pin side-brazed ceramic DIP.

High Reliability Devices

See pages 5-4 and 5-5 for MILITARY STANDARD Process Flows and Ordering Information.

Features

- ☐ Free from secondary breakdown
- ☐ Low power drive requirement
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- ☐ Convertors
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- ☐ Switches
- ☐ Power supply circuits
- ☐ Driver (Relays, Hammers, Solenoids, Lamps, Memories, Displays, Bipolar Transistors, etc.)

Absolute Maximum Ratings

Drain-to-Source Voltage	BV_{DSS}
Drain-to-Gate Voltage	BV_{DGS}
Gate-to-Source Voltage	± 30V
Operating and Storage Temperature	-55°C to +150°C
Soldering Temperature*	300°C

* Distance of 1.6 mm from case for 10 seconds.

Advanced DMOS Technology

These enhancement-mode (normally-off) DMOS power Fet Arrays utilize a vertical DMOS structure and Supertex's well-proven silicon-gate manufacturing process. This combination produces devices with the power handling capabilities of bipolar transistors and with the high input impedance and positive temperature coefficient inherent in MOS devices. Characteristic of all MOS structures, these devices are free from thermal runaway and thermally-induced secondary breakdown.

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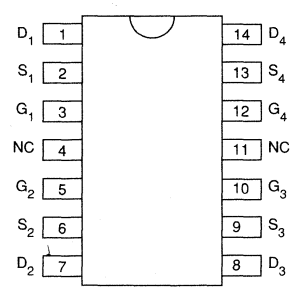
Pin Configuration



top view

14-pin DIP

Thermal Characteristics (T_A = 25°C)

Test	Unit	Each Transistor	All Four Transistors
Total Power Dissipation	Watts	1.3	2.0
Thermal Resistance	°C/W	96.2	62.5
Continuous Drain Current	A	-0.41	—
Pulsed Drain Current	A	-3.0	—

Electrical Characteristics (@ 25°C unless otherwise specified)

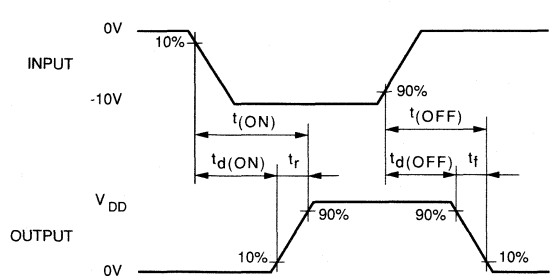
(Notes 1 and 2)

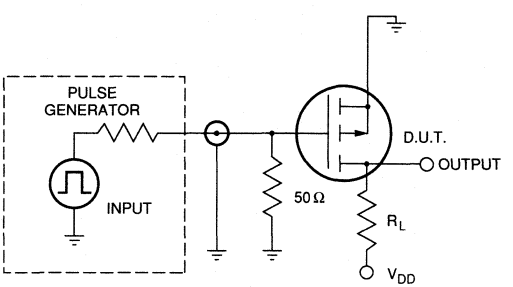
Symbol	Parameter	Min	Typ	Max	Unit	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	-90			V	V_{GS} = 0V, V_{DS}= -10µA
$V_{GS(th)}$	Gate Threshold Voltage	-1.4	-1.8	-4.5	V	V_{GS} = V_{DS}, I_D = -1mA
I_{GSS}	Gate Body Leakage			100	nA	V_{GS} = ±30V, V_{DS} = 0
I_{DSS}	Zero Gate Voltage Drain Current			-10	µA	V_{GS} = 0V, V_{DS}= Max Rating
				-500		V_{GS} = 0V, V_{DS} = 0.8 Max Rating, T_A = 125°C
$I_{D(ON)}$	ON-State Drain Current	-1.0			A	V_{GS} = -10V, V_{DS} = -10V
$R_{DS(ON)}$	Static Drain-to-Source ON-State Resistance		2.5	5.0	Ω	V_{GS} = -10V, I_D = -1A
G_{FS}	Forward Transconductance	200			m℧	V_{DS} = -10V, I_D = -0.5mA
C_{ISS}	Input Capacitance			150	pF	V_{GS} = 0, V_{DS} = -25V, f = 1 MHz
C_{OSS}	Common Source Output Capacitance			65		
C_{RSS}	Reverse Transfer Capacitance			25		
$t_{d(ON)}$	Turn-ON Delay Time			55	ns	V_{DD} = -25V, I_D = -0.5A
$t_{d(OFF)}$	Turn-OFF Delay Time			60	ns	R_S = 50Ω
V_{SD}	Diode Forward Voltage Drop			1.8	V	V_{GS} = 0, I_{SD} = 1A

Notes:
1. All D.C. parameters 100% tested at 25°C unless otherwise stated. (Pulse test: 300µs pulse, 2% duty cycle.)
2. All A.C. parameters sample tested.

10

Switching Waveforms and Test Circuit





Supertex inc.

High-Voltage Integrated Circuit Custom Design and Process Capabilities

HVIC Custom Capabilities

Supertex, Inc. is a supplier of technologically-advanced high-voltage MOS transistors and integrated circuits. The standard devices in our catalogs are found in military, industrial and commercial applications requiring high voltage, high packing density, low turn-on thresholds, and logic-plus-power on the same chip, known as high voltage integrated circuits (HVIC).

Some of the special applications of our HVICs include drivers for printer heads and plotters, flat panel displays (including Plasma and Electroluminescent, Vacuum Fluorescent and Liquid Crystal displays), medical ultrasound transducers, and bare-board testers. Our special high-voltage manufacturing and design capabilities have been used for several years to provide unique solutions for many customers. The capability summary shown here provides a brief overview of current Supertex custom capabilities to design and manufacture HVICs. These HVICs provide not only proprietary protection for our customers, but also offer them improved performance, lower power dissipation, better reliability, space savings and above all, lower total system cost.

High-Voltage Circuit Design

Supertex provides over ten years of experience in High Voltage Integrated Circuit Design with true Complementary N–Channel and P–Channel output configurations. These may be output devices for push-pull drive, or for fast pull-up or pull-down, providing high density with cost effectiveness. Supertex also offers proprietary low-power level translators for driving high-side drivers with minimal quiscent dissipation.

By design, our logic circuitry is particularly latch-up resistant for increased reliability in noisy environments. This is especially important because many circuits need to perform beyond 20MHz, as in high speed graphic equipment. Where higher speeds are needed, multiple shift registers can be put on a chip for parallel multiplex feeds to conserve power dissipation.

Standard High-Voltage Processes

The foundation for any semiconductor manufacturer is process technology. At Supertex, we have developed and refined a family of high-voltage CMOS/DMOS processes, working closely with our customers for over ten years. They are summarized as follows:

HVCMOS I: 160V or ±80V analog switch with 12V CMOS logic

HVCMOS II-S1: 80V push-pull, 400V open drain plus 5 or 12V CMOS logic

HVCMOS II-S2: 275V push-pull with 5 or 12V CMOS logic

HVCMOS III: 200V bilateral analog switch with 5V or 12V CMOS logic

The choice of 5V or 12V is usually dictated by logic interface (5V) or noise-immunity and higher turn-on (12V) requirements. These processes produce truly low power CMOS designs. Our HVICs have low power dissipation that are uniquely suitable for low cost high pin count packages.

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Custom Product Capability Summary

	Open-Drain Outputs (N-Channel or P-Channel)	Complementary Push-Pull Outputs	Analog Output
Output Breakdown Voltage	30V–400V	30V–275V	30V–160V
Output Current	10µA–3A	10µA–1A	10µA–1A
Number of Outputs	1–160	1–160	1–32
Logic Supply Voltage	5V or 12V		
Package Material	Ceramic or Plastic		
Package Types	J-Lead (PLCC), Gullwing†, DIP, or Dice		
Temperature Ranges	0° to 70°C (commerical), -40° to 85°C (industrial), -55° to 125°C (military)		
Technologies	CMOS/DMOS, Analog, Digital, or Mixed Signal		
Frequencies	DC to Video		100kHz

†Flat packs with leads on 3 or 4 sides

Packages and Die Options

One of our main strengths is providing the advantages of high-voltage ICs in high pin count packages.

We can provide:

- Standard QFP packages up to 100 leads
- Special packages for more than 84 leads
- J-lead(PLCC), gullwing, or DIP Packages
- Small-outline packages
- Custom lead frames and special lead bends
- Hybrids and arrays

These offerings provide space efficiency and reduced insertion costs to our customers. They are particularly appropriate in flat-panel displays and printer assemblies as well as other applications where space is at a premium. All offerings are available in industrial temperature range versions, and most can also be supplied as military versions as well.

For the ultimate packaging density, we can supply dice. Using pad pitches down to 100 microns or less, with aspect ratios up to 7 to 1, optimum interface to printers and displays can be achieved. The user thus has several choices: Die in waffle pack, in wafer form, or as bumped die for tape automated bonding (TAB); chip-on-glass or die on printed circuit board. All of these offer cost and space savings. However, packaged products provide testability and field repairability as well as the capability of machine (robot) insertion or placement.

Quality Monitoring

The latest statistical methods are used to raise quality levels. Statistical Quality Control (SQC) is an ongoing tightening of such levels in-process.

Our Parts per Million (PPM) program is a continual feedback loop to ensure conformance to the customer's specifications using computerized data generated from each processed lot. Custom parts receive the same benefits from our Quality and Reliability programs as standard parts. Supertex routinely supplies 883C parts to manufacturers of military equipment.

Reliability

We also have in-house activities to ensure the reliability of our products in the field. These include:

Reliability Monitoring Program - lot samples are tested and monitored on a periodic basis for infant mortalities and long-term degradation.

Failure Analysis Laboratory - we have our own lab on the premises, with SEM, SRP, LCD thermal, and other analytical equipment. This lab enables us to get fast feedback for corrective action whenever necessary.

Our R & D departments are continually developing improved circuit & processing techniques for raising the Electrostatic Discharge (ESD) protection on our devices (presently at ±2KV). Manufactured parts are put in conductive plastic tubes to protect them in shipment. All assembly facilities are meticulously inspected for adherence to ESD procedures.

Solutions to Design Needs

Supertex has a proven track record in the development and production of custom and semi-custom high voltage integrated circuits. Since its inception in 1976, Supertex has provided custom solutions for computers, military, telecommunications, medical instrumentation, and consumer products. Based on its pioneering HVCMOS technology, and supported by a staff with uniquely diverse expertise and experience, Supertex provides the research and development environment which provides its customers with the most advanced solutions to custom and semi-custom HVIC requirements. A thorough understanding of customer requirements by our application engineers and circuit designers results in practical and commercially viable solutions. Working closely with its customers, Supertex develops meaningful time lines and specifications for production and provides continuous progress updates to ensure quality solutions on a timely basis.

If your product requires a custom or semi-custom high voltage integrated circuit, Supertex can provide you with the resources necessary to accomplish your goals. Contact your nearest Supertex Sales Office or the Sunnyvale Headquarters directly to begin creating the solution to your custom or semi-custom HVIC requirements.

High-Voltage Serial-to-Parallel Converters with Source/Sink Outputs (Push-Pull)

Device Number	Outputs	Logic Configuration	Output Operating Voltage	Output Current Per Channel	Similar Devices	Applications
HV04/ HV06	64	Serial to parallel converter w/latches, polarity and blanking	80V	±20mA	None	EL column drivers, non-impact printers, LCD displays
HV04H/ HV06H	64	Serial to parallel converter w/latches, polarity and blanking w/hotswitch capability	80V	+20mA -12mA	None	EL column drivers, non-impact printers, LCD displays
HV09	32	Serial to parallel converter w/ direction, polarity and output enable	230V	±200mA	None	EL/Plasma row drivers particularly with high refresh rates
HV33	32 +22	Serial to parallel converter with strobe	36V	±4mA	None	Printhead driver
HV34	64	Serial to parallel converter w/latches, polarity and blanking, V_{DD} = 5V	180V	±5mA	None	Ink-jet printers, LCD drivers
HV38	32	Grey shade column driver w/ 16 analog levels	60V	±15mA	None	Video and grey shade EL and LCD displays
HV53/ HV54	32	Serial to parallel converter w/latches, output enable	80V	±20mA	*Siliconix SI 9553/9554 *TI SN75555/75556 *Sprague UCN5853/5854	EL column drivers and non-impact printers LCD Drivers
HV57/ HV58	32	Serial to parallel converter w/latches, polarity and blanking	80V	±20mA	Siliconix SI9553/9554 TI SN75555/75556 Sprague UCN5853/5854	Non-impact printers and plotters, EL displays, LCD drivers
HV500	32	AC plasma driver with multiplexed 8-bit shift register	100V	±15mA	*TI SN75500/55500	AC plasma display drivers, printer
HV501	32	Serial to parallel AC plasma driver with shift register	100V	±15mA	*TI SN75501/55501	AC plasma display drivers, printer
HV518	32	Serial to parallel converter w/ latch enable and strobe pins	90V	10mA	TI SN75518 Sprague VCN5818-1	Plasma and Vacuum fluorescent display driver
HV60	32	LCD driver w/active return to ground	±40V	±15mA	None with return to GND capability	High voltage LCD displays
HV61	32	Serial to parralel converter	10V	±1mA	None	LCD displays
HV67	32	Serial to parallel converter w/backplane output	80V	±20mA -5mA	* Siliconix SI9530 * TI SN75555/75556	EL column drivers, non-impact printers, LCD display drivers
HV6810	10	Serial to parallel converter w/latches	80V	+25mA -4mA	TI TL4810 Sprague UCN5810	Vacuum Fluorescent display drivers
HV70	34	Serial to parallel converter w/ polarity and output enable	230V	±70mA	*TI SN755563 SN755564	EL row driver for EL, Plasma and other panels

High-Voltage Serial-to-Parallel Converters with Source/Sink Outputs (Push-Pull)(Continued)

Device Number	Outputs	Logic Configuration	Output Operating Voltage	Output Current Per Channel	Similar Devices	Applications
HV72	40	Serial to parallel converter w/polarity, output enable,	250V	±72mA	NEC μPD16302	AC TFEL row drivers
HV77	64	Serial to parallel converter w/ four 16 bit shift registers	80V	±20mA	None	EL row drivers with high data throughput
HV78	64	Serial to parallel converter w/ two 32 bit shift registers	80V	±20mA	None	EL row drivers with high data throughput
HV701/ HV711	40	Serial to parallel VF driver w/shift register	220V	+0.5mA -3.0mA	TI 755701/711	Vacuum-fluorescent displays
HV702/ HV712	40	Serial to parallel VF driver w/shift register	220V	+2.5mA -10mA	TI 755702/712	Vacuum-fluorescent displays
HV83/ HV84	32	Serial to parallel converter w/latches output enable, V_{DD} = 5V	80V	±20mA	* Siliconix SI9553/9554 * TI SN75555/7556 * Sprague UCN5853/5854	EL column drivers, non-inpact printers, LCD display
HV87/ HV88	32	Serial to parallel converter w/latches, polarity and blanking, V_{DD} = 5V	80V	±20mA	Siliconix SI9553/9554 TI SN75555/7556 Sprague UCN 5853/5854	EL column drivers, non-impact printers/plotter, displays, LCD drivers
HV93/ HV94	32	Serial to parallel converter w/latches output enable, V_{DD} = 5V	80V	+20mA -5mA	* Siliconix SI9553/9554 * TI SN75555/7556 * Sprague UCN5853/5854	EL column drivers, non-inpact printers, LCD display
HV97/ HV98	32	Serial to parallel converter w/latches, polarity and blanking V_{DD} = 5V	80V	±20mA	Siliconix SI9553/9554 TI SN75555/75556 Sprague UCN5853/5854	Non-impact printers and plotters, EL displays, LCD drivers

*Pin compatible direct replacement.

High-Voltage Serial-to-Parallel Converters with Sink-Only Outputs (Open Drain N-Channel)

Device Number	Outputs	Output Logic Configuration	Output Operating Voltage	Current Per Channel	Direct Competitive Devices	Applications
HV03 HV05	64	Serial to parallel converter w/latches, Supertex logic	300V	+100mA	None	EL row drivers, non-impact printers/plotters
HV31	64	Serial to parallel converter w/ output enable	375V	+1mA	None	Electrostatic printers
HV51 HV52	32	Serial to parallel converter w/output enable and strobe	220V	+100mA	*TI 75551/75552 *Siliconix Si9551/9552 *Sprague UCN5851/5852	EL row driver, non-impact printers/ plotters
HV55 HV56	32	Serial to parallel converter w/latches, polarity and blanking	220V, 300V	+100mA	TI 75551/75552 Siliconix Si9551/9552 Sprague UCN5851/5852	Non-impact printers/ plotters, EL row drivers

*Pin compatible direct replacement

High-Voltage Serial-to-Parallel Converters with Source-Only Outputs (Open Drain P-Channel)

Device Number	Out-puts	Logic Configuration	Output Operating Voltage	Output Current Per Channel	Similar Devices	Applications
HV41 HV42	32	Serial to parallel converter w/output enable and strobe	-220V	-80mA	Sharp	EL row drivers, non-impact printers
HV45 HV46	32	Serial to parallel converter w/latches, polarity and blanking	-220V, - 300V	-60mA	Sharp	Non-impact printers and plotters, EL display row drivers
HV49	64	Serial to parallel converter	-375V	-1mA	None	Electrostatic printers

High-Voltage Analog Switches

Device Number	Switches	Switch Operating Configuration	Maximum Switch Resistance	Similar Devices	Applications
HV341	Dual SPST	100V P-P	110 ohms	MAX 341	High voltage switching, mil electronics & instrumentation
HV343	Dual SPDT	100V P-P	110 ohms	MAX 343	High voltage switching, mil electronics & instrumentation
HV345	Dual DPST	100V P-P	110 ohms	MAX 345	High voltage switching, mil electronics & instrumentation
HV348	Dual SPST	100V P-P	55 ohms	MAX 348	High voltage switching, mil electronics & instrumentation

High-Voltage Bilateral Switches

Device Number	Switches	Logic Configuration	Maximum Switch Voltage	Peak Switch Current	Applications
HV10	4	Parallel inputs, latches	160V P-Supp latches	±3.0A 130V P-P Sig	Medical ultrasound, HV multiplexers, Ink jet printers
HV12	8	Shift register, latches	160V P-Supp 130V P-P Sig	±1.5A	Medical ultrasound, HV multiplexers, Ink jet printers
HV14	8	Decoders, latches, chip select and data in	160V P-Supp 130V P-Sig	±1.5A	Medical ultrasound, HV multiplexers, Ink jet printers
HV15	8	Decoders, latches and chip selects	160V P-Supp 130V P-Sig	±1.5A	Medical ultrasound, HV multiplexers, Ink jet printers
HV16	8	Shift register, latches	160V P-Supp 130V P-Sig	±1.5A	Medical ultrasound, HV multiplexers, Ink jet printers
HV18	8	Shift register, latches and clear	160V P-Supp 130V P-Sig	±1.5.A	Medical ultrasound, HV multiplexers, Ink jet printers
HV21	8	Shift register, latches	160V P-Supp 140V P-Sig	±2.0A	Medical ultrasound, HV multiplexers, Ink jet printers
HV22	8	Shift register, latches and clear	160V P-Supp 140V P-Sig	±2.0A	Medical ultrasound, HV multiplexers, Ink jet printers

High-Voltage Off-line Switchmode Controllers

Device Number	+ V_{IN} Volts		Feedback Voltage	On-board Output MOSFET	Similar Devices	Applications
	Min	Max				
HV9100	10	70	±1%	Yes	Siliconix SI9100 Teledyne TSC9100	DC/DC converters Distributed Power Systems
HV9101	10	70	±10%	Yes	Siliconix SI9101 Teledyne TSC9101	DC/DC converters Distributed Power Systems
HV9110	10	120	±1%	No	Siliconix SI9110 Teledyne TSC9110	DC/DC converters Distributed Power Systems
HV9111	10	120	±10%	No	Siliconix SI9111 Teledyne TSC9111	DC/DC converters Distributed Power Systems
HV9120	10	450	±2%	No	Siliconix SI9120 Teledyne TSC9116	DC/DC converters Distributed Power Systems

64-Channel Serial To Parallel Converter With Open Drain Outputs

Ordering Information

Device	Recommended Operating V_{PP} Max	Package Options				
		80-Lead Quad Cerpak Gullwing	80-Lead Quad Plastic Gullwing	80-Lead 35mm TAB Tape	Die	80-Lead Quad Cerpak Gullwing (MIL-STD-883 Processed*)
HV03	220V	HV0322DG	HV0322PG	HV0322T	HV0322X	RBHV0322DG
	300V	HV0330DG	HV0330PG	HV0330T	HV0330X	—
HV05	220V	HV0522DG	HV0522PG	HV0522T	HV0522X	RBHV0522DG
	300V	HV0530DG	HV0530PG	HV0530T	HV0530X	—

*For Hi-Rel process flows, please refer to page 5-3 in the Databook.

Features

- ☐ HVCMOS® Technology
- ☐ Output voltages up to 300V using a ramped supply
- ☐ Sink current minimum 100 mA
- ☐ Shift register speed 8 MHz
- ☐ Latched outputs
- ☐ Output polarity and blanking
- ☐ CMOS compatible inputs
- ☐ Forward and reverse shifting options

Absolute Maximum Ratings[1]

Supply voltage, V_{DD}		-0.5V to +15V
Supply voltage, V_{PP}[2]		-0.5V to +315V
Logic input levels		-0.5V to V_{DD} +0.5V
Ground current[3]		6.0A
Continuous total power dissipation[4]	Ceramic	1900mW
	Plastic	1200mW
Operating temperature range	Ceramic	-40°C to +85°C
	Plastic	0°C to +70°C
Storage temperature range	-65°C to +150°C	

Notes:
1. All voltages are referenced to GND.
2. These devices have been designed to be used in applications which either switch the V_{PP} supply to ground before changing the state of the high voltage outputs or limit the current through each output.
3. Connection to all power and ground pads is required. Duty cycle is limited by the total power dissipated in the package.
4. For operation above 25°C ambient derate linearly to 85°C at 15mW/°C.

General Description

The HV03 and HV05 are low voltage serial to high voltage parallel converters with open drain outputs. These devices have been designed for use as drivers for AC-electroluminescent displays. They can also be used in any application requiring multiple output high voltage current sinking capabilities such as driving inkjet and electrostatic printheads, plasma panels, vacuum fluorescent, or large matrix LCD displays.

These devices consist of a 64-bit shift register, 64 latches, and control logic to perform the polarity select and blanking of the outputs. Data is shifted through the shift register on the high to low transition of the clock. The HV03 shifts in the counterclockwise direction when viewed from the top of the package and the HV05 shifts in the clockwise direction. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register. Operation of the shift register is not affected by the $\overline{LE}$ (latch enable), $\overline{BL}$ (blanking), or the $\overline{POL}$ (polarity) inputs. Transfer of data from the shift register to the latch occurs when the $\overline{LE}$ (latch enable) input is high. The data in the latch is stored when $\overline{LE}$ is low.

The HV03 and HV05 have been designed to be used in systems which either switch off the high voltage supply before changing the state of the high voltage outputs or limit the current through each output.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Typ	Max	Units	Conditions
I_{DD}	V_{DD} Supply Current				25	mA	f_{CLK} = 8MHz, f_{DATA} = 4MHz $\overline{LE}$ = LOW
I_{DDQ}	Quiescent V_{DD} Supply Current				0.25	mA	All V_{IN} = 0V
$I_{O(OFF)}$	Off State Output Current				100	µA	All outputs high, All SWS parallel
I_{IH}	High-Level Logic Input Current				10	µA	$V_{IH} = V_{DD}$
I_{IL}	Low-Level Logic Input Current				-10	µA	V_I = 0V
V_{OH}	High-Level Output Data Out		V_{DD} -1V			V	ID_{OUT} = -100µA
V_{OL}	Low-Level Output	HV_{OUT}			15	V	IHV_{OUT} = +100mA
		Data Out			1	V	ID_{OUT} = +100µA
V_{OC}	HV_{OUT} Clamp Voltage				-1.5	V	I_{OL} = -100mA

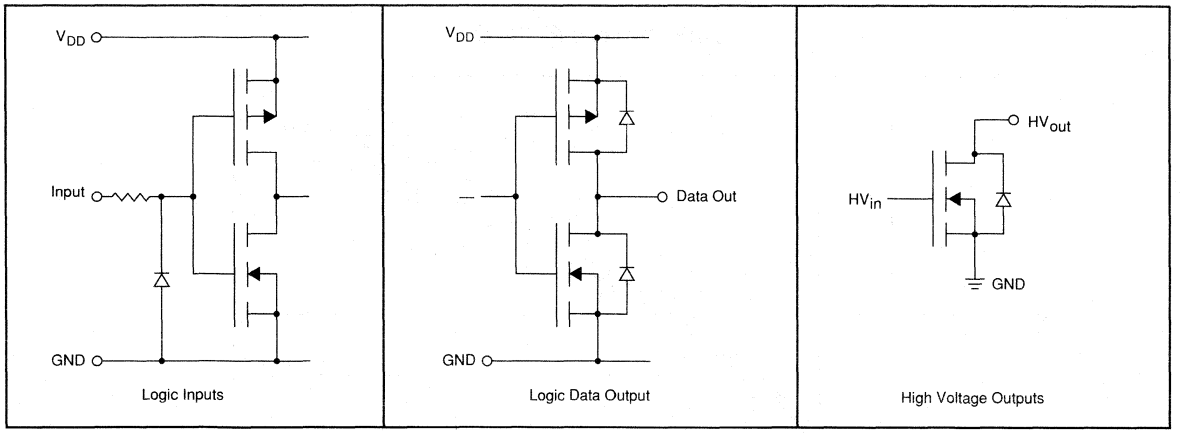
AC Characteristics

Symbol	Parameter	Min	Typ	Max	Units	Conditions
f_{CLK}	Clock Frequency			8	MHz	
t_W	Clock Width High or Low	62			ns	
t_{SU}	Data Setup Time Before Clock Falls	25			ns	
t_H	Data Hold Time After Clock Falls	10			ns	
t_{WLE}	Width of Latch Enable Pulse	62			ns	
t_{DLE}	$\overline{LE}$ Delay Time Falling Edge of Clock	25			ns	
t_{SLE}	$\overline{LE}$ Setup Time Before Falling Edge of Clock	30			ns	
t_D	Delay Time from V_{PP} Low Until Change in $\overline{LE}$, $\overline{POL}$, $\overline{BL}$ Is Allowed	100			ns	
t_{SL}	Setup Time from Falling Edge $\overline{LE}$ to V_{PP} Rise	200			ns	
t_{SB}	Setup Time from $\overline{BL}$ Selected to V_{PP} Rise	150			ns	
t_{SP}	Setup Time from $\overline{POL}$ Selected to V_{PP} Rise	100			ns	
t_{DHL}	Delay Time Clock to Data High to Low			100	ns	
t_{DLK}	Delay Time Clock to Data Low to High			100	ns	

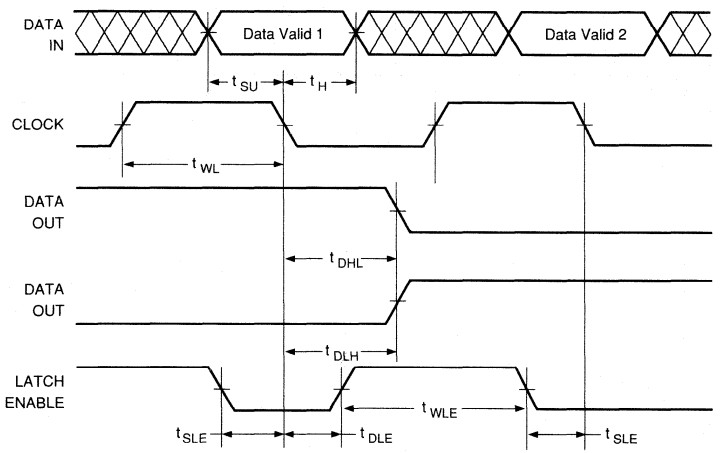
Recommended Operating Conditions

Symbol	Parameter		Min	Typ	Max	Units
V_{DD}	Logic supply voltage		10.8	12	13.2	V
V_{PP}	High voltage supply	HV0322/HV0522	-0.3		200	V
		HV0330/HV0530	-0.3		300	V
V_{IH}	High-level input voltage		V_{DD} - 2V		V_{DD}	V
V_{IL}	Low-level input voltage		0		2.0	V
dV/dt	V_{PP} ramp rate				80	V/µs
T_A	Operating free-air temperature		-40		+85	°C

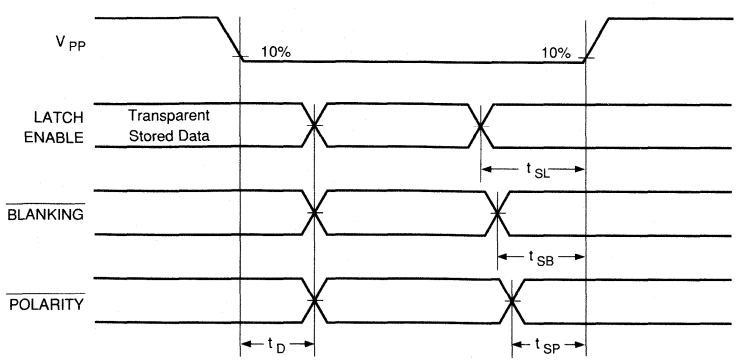
Input and Output Equivalent Circuit



Switching Waveforms

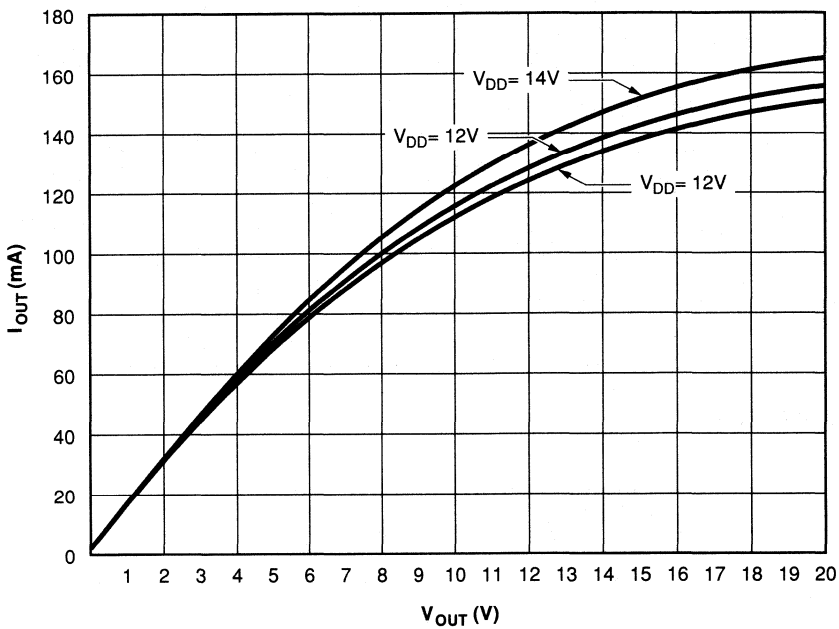


Output Control Waveforms

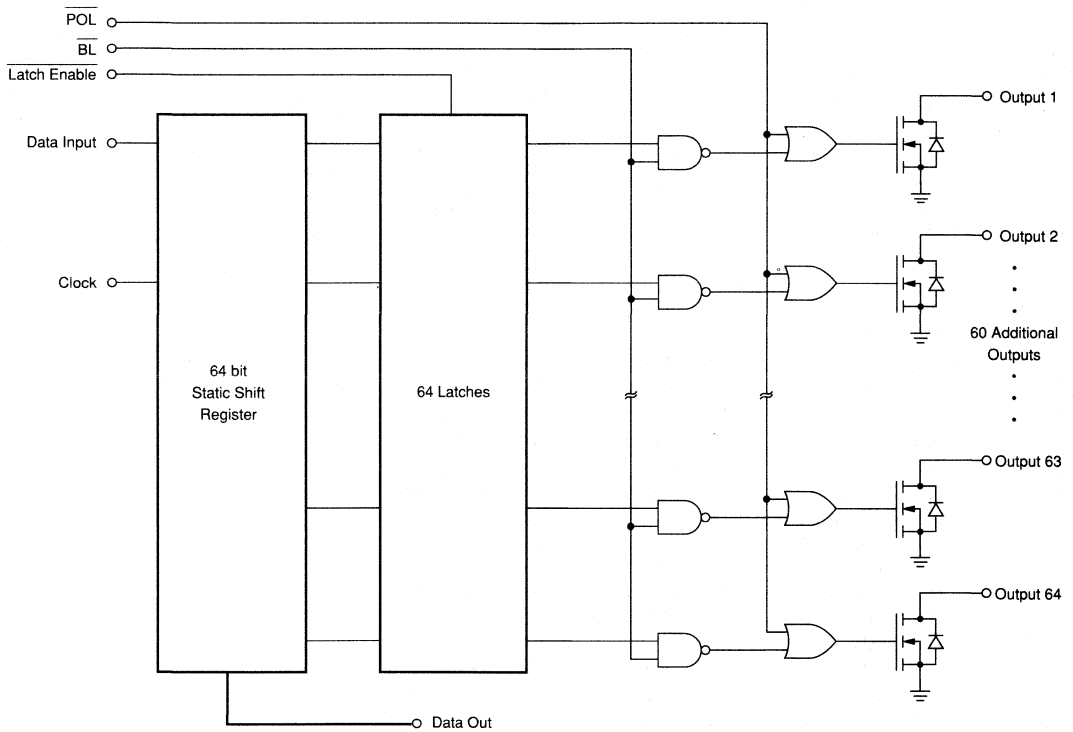


Typical Operating Conditions

Sink Current @ 25°C



Functional Block Diagram



Function Table

Function	Inputs					Outputs		
	Data	CLK	$\overline{LE}$	$\overline{BL}$	$\overline{POL}$	Shift Reg 1 2...64	HV Outputs 1 2...64	Data Out *
All on	X	X	X	L	L	* *...*	L L...L	*
All off	X	X	X	L	H	* *...*	H H...H	*
Invert mode	X	X	L	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Load S/R	H or L	↓	L	H	H	H or L *...*	* *...*	*
Load Latches	X	X	H	X	X	* *...*	* *...*	*
Transparent Latch mode	L	↓	H	H	H	L *...*	H *...*	*
	H	↓	H	H	H	H *...*	L *...*	*

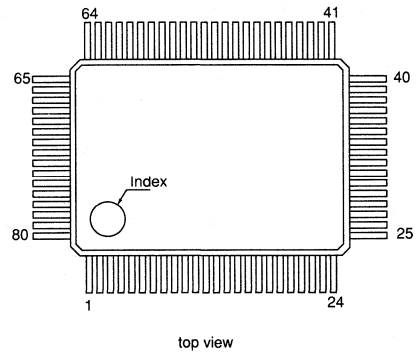
Notes:
H = high level, L = low level, X = irrelevant, ↓= high-to-low transition.
* = dependent on previous stage's state before the last CLK or last LE high,

Pin Configurations

PG and DG Packages

HV03				HV05			
Pin	**Function**	**Pin**	**Function**	**Pin**	**Function**	**Pin**	**Function**
1	GND	41	GND	1	GND	41	GND
2	GND	42	GND	2	GND	42	GND
3	HV_{OUT} 59	43	HV_{OUT} 23	3	HV_{OUT} 6	43	HV_{OUT} 42
4	HV_{OUT} 60	44	HV_{OUT} 24	4	HV_{OUT} 5	44	HV_{OUT} 41
5	HV_{OUT} 61	45	HV_{OUT} 25	5	HV_{OUT} 4	45	HV_{OUT} 40
6	HV_{OUT} 62	46	HV_{OUT} 26	6	HV_{OUT} 3	46	HV_{OUT} 39
7	HV_{OUT} 63	47	HV_{OUT} 27	7	HV_{OUT} 2	47	HV_{OUT} 38
8	HV_{OUT} 64	48	HV_{OUT} 28	8	HV_{OUT} 1	48	HV_{OUT} 37
9	POL	49	HV_{OUT} 29	9	POL	49	HV_{OUT} 36
10	Data Out	50	HV_{OUT} 30	10	Data Out	50	HV_{OUT} 35
11	CLK	51	HV_{OUT} 31	11	CLK	51	HV_{OUT} 34
12	GND	52	HV_{OUT} 32	12	GND	52	HV_{OUT} 33
13	V_{DD}	53	HV_{OUT} 33	13	V_{DD}	53	HV_{OUT} 32
14	LE	54	HV_{OUT} 34	14	LE	54	HV_{OUT} 31
15	$\overline{\text{Data In}}$	55	HV_{OUT} 35	15	$\overline{\text{Data In}}$	55	HV_{OUT} 30
16	$\overline{\text{BL}}$	56	HV_{OUT} 36	16	$\overline{\text{BL}}$	56	HV_{OUT} 29
17	HV_{OUT} 1	57	HV_{OUT} 37	17	HV_{OUT} 64	57	HV_{OUT} 28
18	HV_{OUT} 2	58	HV_{OUT} 38	18	HV_{OUT} 63	58	HV_{OUT} 27
19	HV_{OUT} 3	59	HV_{OUT} 39	19	HV_{OUT} 62	59	HV_{OUT} 26
20	HV_{OUT} 4	60	HV_{OUT} 40	20	HV_{OUT} 61	60	HV_{OUT} 25
21	HV_{OUT} 5	61	HV_{OUT} 41	21	HV_{OUT} 60	61	HV_{OUT} 24
22	HV_{OUT} 6	62	HV_{OUT} 42	22	HV_{OUT} 59	62	HV_{OUT} 23
23	GND	63	GND	23	GND	63	GND
24	GND	64	GND	24	GND	64	GND
25	HV_{OUT} 7	65	HV_{OUT} 43	25	HV_{OUT} 58	65	HV_{OUT} 22
26	HV_{OUT} 8	66	HV_{OUT} 44	26	HV_{OUT} 57	66	HV_{OUT} 21
27	HV_{OUT} 9	67	HV_{OUT} 45	27	HV_{OUT} 56	67	HV_{OUT} 20
28	HV_{OUT} 10	68	HV_{OUT} 46	28	HV_{OUT} 55	68	HV_{OUT} 19
29	HV_{OUT} 11	69	HV_{OUT} 47	29	HV_{OUT} 54	69	HV_{OUT} 18
30	HV_{OUT} 12	70	HV_{OUT} 48	30	HV_{OUT} 53	70	HV_{OUT} 17
31	HV_{OUT} 13	71	HV_{OUT} 49	31	HV_{OUT} 52	71	HV_{OUT} 16
32	HV_{OUT} 14	72	HV_{OUT} 50	32	HV_{OUT} 51	72	HV_{OUT} 15
33	HV_{OUT} 15	73	HV_{OUT} 51	33	HV_{OUT} 50	73	HV_{OUT} 14
34	HV_{OUT} 16	74	HV_{OUT} 52	34	HV_{OUT} 49	74	HV_{OUT} 13
35	HV_{OUT} 17	75	HV_{OUT} 53	35	HV_{OUT} 48	75	HV_{OUT} 12
36	HV_{OUT} 18	76	HV_{OUT} 54	36	HV_{OUT} 47	76	HV_{OUT} 11
37	HV_{OUT} 19	77	HV_{OUT} 55	37	HV_{OUT} 46	77	HV_{OUT} 10
38	HV_{OUT} 20	78	HV_{OUT} 56	38	HV_{OUT} 45	78	HV_{OUT} 9
39	HV_{OUT} 21	79	HV_{OUT} 57	39	HV_{OUT} 44	79	HV_{OUT} 8
40	HV_{OUT} 22	80	HV_{OUT} 58	40	HV_{OUT} 43	80	HV_{OUT} 7

Package Outline



top view

80-pin Gullwing Package

64-Channel Serial To Parallel Converter With High Voltage CMOS Outputs

Ordering Information

Device	Recommended Operating V_{PP} Max	Package Options				
		80-Lead Quad Cerpak Gullwing	80-Lead Quad Plastic Gullwing	80-Lead 35mm TAB Tape	Die	80-Lead Quad Cerpak Gullwing (MIL-STD-883 Processed*)
HV04	60V	HV0406DG	HV0406PG	HV0406T	HV0406X	—
	80V	HV0408DG	HV0408PG	HV0408T	HV0408X	RBHV0408DG
HV06	60V	HV0606DG	HV0606PG	HV0606T	HV0606X	—
	80V	HV0608DG	HV0608PG	HV0608T	HV0608X	RBHV0608DG

* For Hi-Rel process flows, please refer to page 5-3 in the Databook

Features

- ☐ HVCMOS® Technology
- ☐ Output voltages up to 90V using a ramped supply
- ☐ Low power level shifting
- ☐ Shift register speed 8 MHz
- ☐ Latched data outputs
- ☐ Output polarity and blanking
- ☐ CMOS compatible inputs
- ☐ Forward and reverse shifting options

Absolute Maximum Ratings[1]

Supply voltage, V_{DD}		-0.5V to +15V
Supply voltage, V_{PP}[2]		-0.5V to +90V
Logic input levels		-0.5V to V_{DD} +0.5V
Ground current[3]		3.0A
High voltage supply current[3]		2.6A
Continuous total power dissipation[4]	Ceramic Plastic	1900mW 1200mW
Operating temperature range	Ceramic Plastic	-40°C to +85°C 0°C to +70°C
Storage temperature range		-65°C to +150°C

Notes:
1. All voltages are referenced to GND.
2. These devices have been designed to be used in applications which either switch the V_{PP} supply to ground before changing the state of the high voltage outputs or limit the current through each output.
3. Connection to all power and ground pads is required. Duty cycle is limited by the total power dissipated in the package.
4. For operation above 25°C ambient derate linearly to 85°C at 15mW/°C.

General Description

The HV04 and HV06 are low voltage serial to high voltage parallel converters with push-pull outputs. These devices have been designed for use as drivers for AC-electroluminescent displays. They can also be used in any application requiring multiple output high voltage current sourcing and sinking capabilities such as driving plasma panels, vacuum fluorescent, or large matrix LCD displays.

These devices consist of a 64-bit shift register, 64 latches, and control logic to perform the polarity select and blanking of the outputs. HVout1 is connected to the first stage of the shift register through the polarity and blanking logic. Data is shifted through the shift register on the low to high transition of the clock. The HV04 shifts in the counterclockwise direction when viewed from the top of the package and the HV06 shifts in the clockwise direction. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register (HVout64). Operation of the shift register is not affected by the $\overline{LE}$ (latch enable), $\overline{BL}$ (blanking), or the $\overline{POL}$ (polarity) inputs. Transfer of data from the shift register to the latch occurs when the $\overline{LE}$ (latch enable) input is high. The data in the latch is stored when $\overline{LE}$ is low.

The HV04 and HV06 have been designed to be used in systems which either switch off the high voltage supply before changing the state of the high voltage outputs or limit the current through each output.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Typ	Max	Units	Conditions
I_{DD}	V_{DD} Supply Current				25	mA	f_{CLK} = 8MHz, f_{DATA} = 4MHz $\overline{LE}$ = LOW
I_{DDQ}	Quiescent V_{DD} Supply Current				0.25	mA	All V_{IN} = 0V
I_{PP}	High Voltage Supply Current				0.50	mA	V_{PP} = 80V All outputs high
					0.50	mA	V_{PP} = 80V All outputs low
I_{IH}	High-Level Logic Input Current				10	µA	$V_{IH} = V_{DD}$
I_{IL}	Low-Level Logic Input Current		-10			µA	V_I = 0V
V_{OH}	High-Level Output	HV_{OUT}	74			V	V_{PP} = 80V, IHV_{OUT} = -20mA
		Data Out	V_{DD} - 1V			V	ID_{OUT} = -100µA
V_{OL}	Low-Level Output	HV_{OUT}			6	V	V_{PP} = 80V, IHV_{OUT} = +10mA
		Data Out			1	V	ID_{OUT} = +100µA
V_{OC}	HV_{OUT} Clamp Voltage				V_{PP} + 1.5	V	I_{OL} = +10mA
					-1.5	V	I_{OL} = -20mA

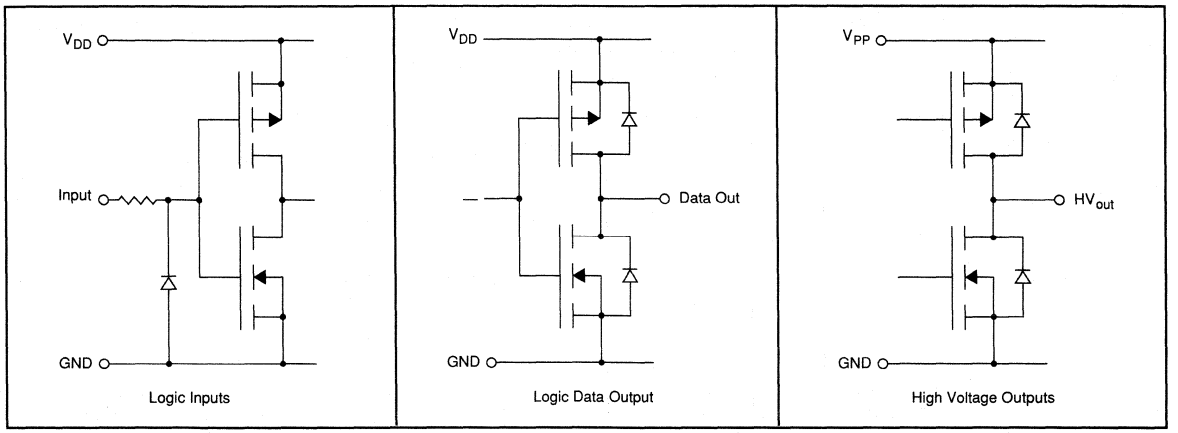
AC Characteristics

Symbol	Parameter	Min	Typ	Max	Units	Conditions
f_{CLK}	Clock Frequency			8	MHz	
t_W	Clock Width High or Low	62			ns	
t_{SU}	Data Setup Time Before Clock Rises	25			ns	
t_H	Data Hold Time After Clock Rises	10			ns	
t_{WLE}	Width of Latch Enable Pulse	62			ns	
t_{DLE}	$\overline{LE}$ Delay Time Rising Edge of Clock	25			ns	
t_{SLE}	$\overline{LE}$ Setup Time Before Rising Edge of Clock	30			ns	
t_D	Delay Time from V_{PP} Low Until Change in $\overline{LE}$, $\overline{POL}$, $\overline{BL}$ Is Allowed	100			ns	
t_{SL}	Setup Time from $\overline{LE}$ Rise to V_{PP} Rise	200			ns	
t_{SB}	Setup Time from $\overline{BL}$ Selected to V_{PP} Rise	150			ns	
t_{SP}	Setup Time from $\overline{POL}$ Selected to V_{PP} Rise	100			ns	
t_{DHL}	Delay Time Clock to Data High to Low			100	ns	
t_{DLH}	Delay Time Clock to Data Low to High			100	ns	

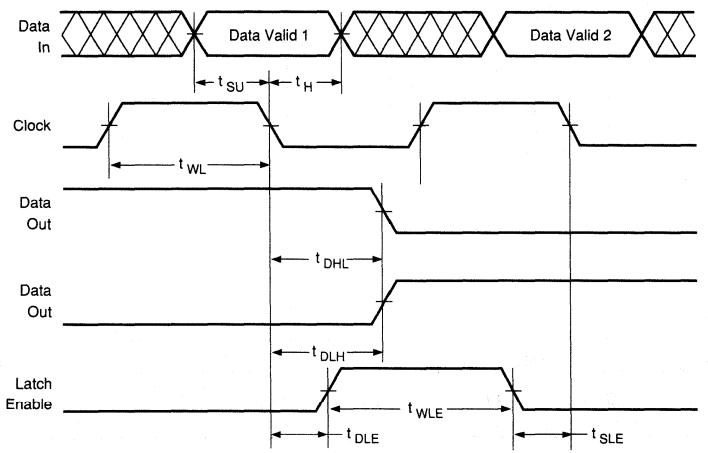
Recommended Operating Conditions

Symbol	Parameter	Min	Typ	Max	Units
V_{DD}	Logic supply voltage	10.8	12	13.2	V
V_{PP}	High voltage supply	-0.3		80	V
V_{IH}	High-level input voltage	V_{DD} - 2V		V_{DD}	V
V_{IL}	Low-level input voltage	0		2.0	V
dV/dt	V_{PP} ramp rate			80	V/µs
T_A	Operating free-air temperature	-40		+85	°C

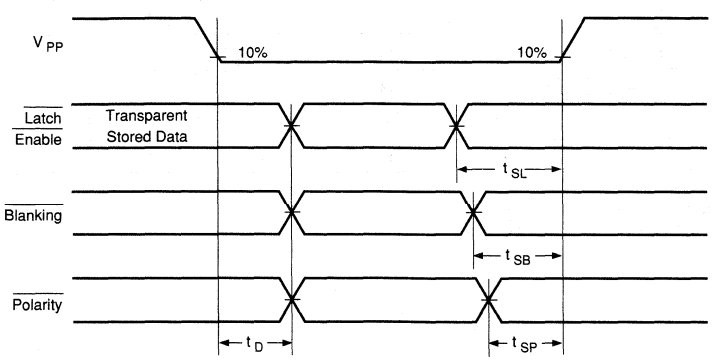
Input and Output Equivalent Circuits



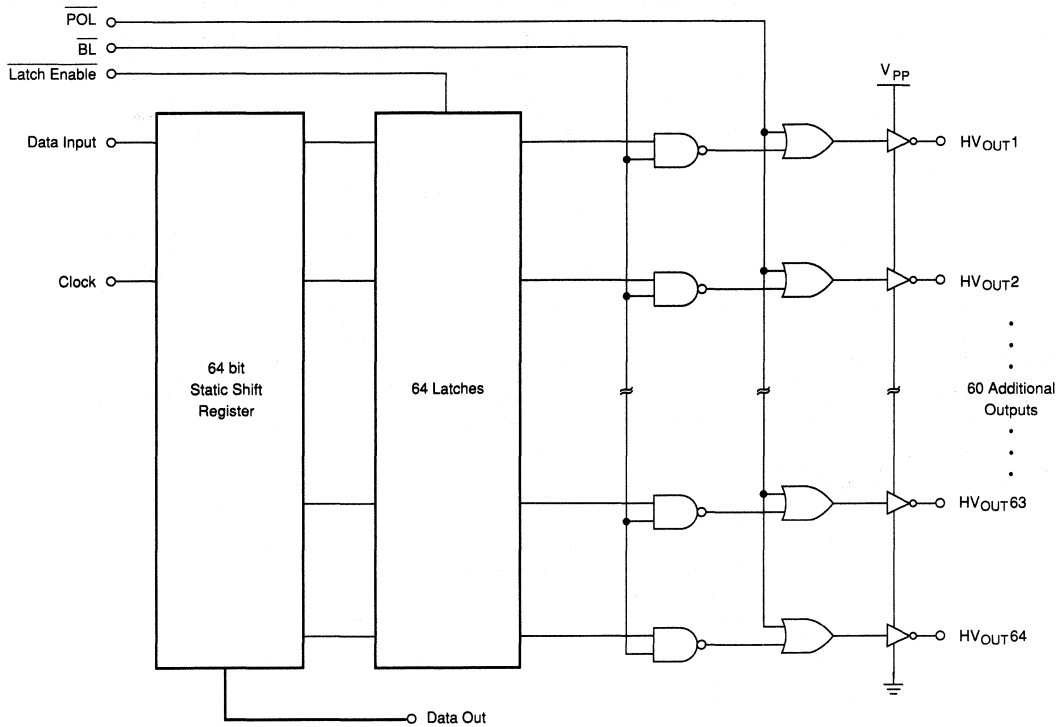
Switching Waveforms



Output Control Waveforms



Functional Block Diagram



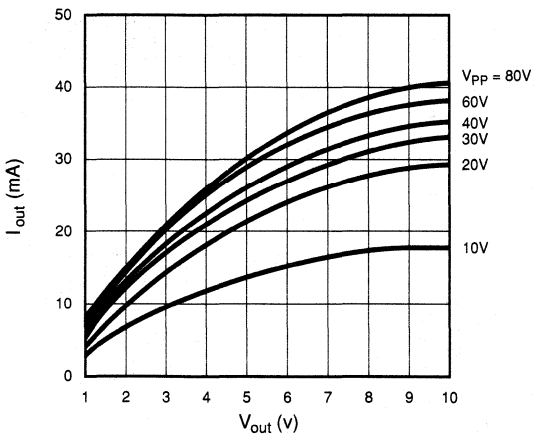
Function Table

Function	Inputs					Outputs		
	Data	CLK	$\overline{LE}$	$\overline{BL}$	$\overline{POL}$	Shift Reg 1 2...64	HV Outputs 1 2...64	Data Out *
All on	X	X	X	L	L	* *...*	H H...H	*
All off	X	X	X	L	H	* *...*	L L...L	*
Invert mode	X	X	L	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Load S/R	H or L	↑	L	H	H	H or L *...*	* *...*	*
Load Latches	X	H or L	H	H	H	* *...*	* *...*	*
	X	H or L	H	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Transparent Latch mode	L	↑	H	H	H	L *...*	L *...*	*
	H	↑	H	H	H	H *...*	H *...*	*

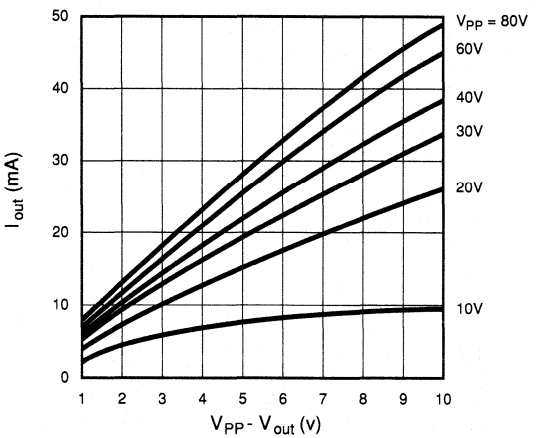
Notes:
H = high level, L = low level, X = irrelevant, ≠ = low-to-high transition.
* = dependent on previous stage's state before the last CLK or last $\overline{LE}$ high,

Typical Performance Curves

Typical HV04/06 Sink Current @ 25°C



Typical HV04/06 Source Current @ 25°C

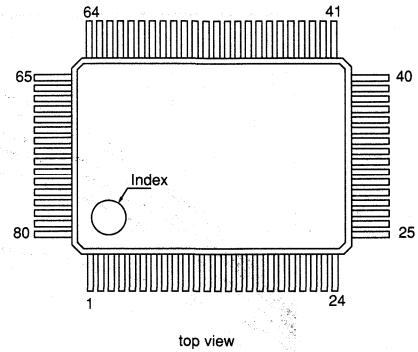


Pin Configurations

PG and DG Packages

HV04				HV06			
Pin	**Function**	**Pin**	**Function**	**Pin**	**Function**	**Pin**	**Function**
1	GND	41	GND	1	GND	41	GND
2	V_{PP}	42	V_{PP}	2	V_{PP}	42	V_{PP}
3	HV_{OUT} 59	43	HV_{OUT} 23	3	HV_{OUT} 6	43	HV_{OUT} 42
4	HV_{OUT} 60	44	HV_{OUT} 24	4	HV_{OUT} 5	44	HV_{OUT} 41
5	HV_{OUT} 61	45	HV_{OUT} 25	5	HV_{OUT} 4	45	HV_{OUT} 40
6	HV_{OUT} 62	46	HV_{OUT} 26	6	HV_{OUT} 3	46	HV_{OUT} 39
7	HV_{OUT} 63	47	HV_{OUT} 27	7	HV_{OUT} 2	47	HV_{OUT} 38
8	$\overline{HV_{OUT}}$ 64	48	HV_{OUT} 28	8	$\overline{HV_{OUT}}$ 1	48	HV_{OUT} 37
9	$\overline{POL}$	49	HV_{OUT} 29	9	$\overline{POL}$	49	HV_{OUT} 36
10	Data Out	50	HV_{OUT} 30	10	Data Out	50	HV_{OUT} 35
11	CLK	51	HV_{OUT} 31	11	CLK	51	HV_{OUT} 34
12	GND	52	HV_{OUT} 32	12	GND	52	HV_{OUT} 33
13	V_{DD}	53	HV_{OUT} 33	13	V_{DD}	53	HV_{OUT} 32
14	$\overline{LE}$	54	HV_{OUT} 34	14	$\overline{LE}$	54	HV_{OUT} 31
15	Data In	55	HV_{OUT} 35	15	Data In	55	HV_{OUT} 30
16	$\overline{BL}$	56	HV_{OUT} 36	16	$\overline{BL}$	56	HV_{OUT} 29
17	HV_{OUT} 1	57	HV_{OUT} 37	17	HV_{OUT} 64	57	HV_{OUT} 28
18	HV_{OUT} 2	58	HV_{OUT} 38	18	HV_{OUT} 63	58	HV_{OUT} 27
19	HV_{OUT} 3	59	HV_{OUT} 39	19	HV_{OUT} 62	59	HV_{OUT} 26
20	HV_{OUT} 4	60	HV_{OUT} 40	20	HV_{OUT} 61	60	HV_{OUT} 25
21	HV_{OUT} 5	61	HV_{OUT} 41	21	HVout 60	61	HV_{OUT} 24
22	HV_{OUT} 6	62	HV_{OUT} 42	22	HV_{OUT} 59	62	HV_{OUT} 23
23	V_{PP}	63	V_{PP}	23	V_{PP}	63	V_{PP}
24	GND	64	GND	24	GND	64	GND
25	HV_{OUT} 7	65	HV_{OUT} 43	25	HV_{OUT} 58	65	HV_{OUT} 22
26	HV_{OUT} 8	66	HV_{OUT} 44	26	HV_{OUT} 57	66	HV_{OUT} 21
27	HV_{OUT} 9	67	HV_{OUT} 45	27	HV_{OUT} 56	67	HV_{OUT} 20
28	HV_{OUT} 10	68	HV_{OUT} 46	28	HV_{OUT} 55	68	HV_{OUT} 19
29	HV_{OUT} 11	69	HV_{OUT} 47	29	HV_{OUT} 54	69	HV_{OUT} 18
30	HV_{OUT} 12	70	HV_{OUT} 48	30	HV_{OUT} 53	70	HV_{OUT} 17
31	HV_{OUT} 13	71	HV_{OUT} 49	31	HV_{OUT} 52	71	HV_{OUT} 16
32	HV_{OUT} 14	72	HV_{OUT} 50	32	HV_{OUT} 51	72	HV_{OUT} 15
33	HV_{OUT} 15	73	HV_{OUT} 51	33	HV_{OUT} 50	73	HV_{OUT} 14
34	HV_{OUT} 16	74	HV_{OUT} 52	34	HV_{OUT} 49	74	HV_{OUT} 13
35	HV_{OUT} 17	75	HV_{OUT} 53	35	HV_{OUT} 48	75	HV_{OUT} 12
36	HV_{OUT} 18	76	HV_{OUT} 54	36	HV_{OUT} 47	76	HV_{OUT} 11
37	HV_{OUT} 19	77	HV_{OUT} 55	37	HV_{OUT} 46	77	HV_{OUT} 10
38	HV_{OUT} 20	78	HV_{OUT} 56	38	HV_{OUT} 45	78	HV_{OUT} 9
39	HV_{OUT} 21	79	HV_{OUT} 57	39	HV_{OUT} 44	79	HV_{OUT} 8
40	HV_{OUT} 22	80	HV_{OUT} 58	40	HV_{OUT} 43	80	HV_{OUT} 7

Package Outline



80-pin Gullwing Package

64-Channel Serial To Parallel Converter With Ruggedized High Voltage CMOS Outputs

Ordering Information

Device	Recommended Operating V_{PP} Max	Package Options				
		80-Lead Quad Cerpak Gullwing	80-Lead Quad Plastic Gullwing	80-Lead 35mm TAB Tape	Die	80-Lead Quad Cerpak Gullwing (MIL-STD-883 Processed*)
HV04H	60V	HV04H06DG	HV04H06PG	HV04H06T	HV04H06X	—
	80V	HV04H08DG	HV04H08PG	HV04H08T	HV04H08X	RBHV04H08DG
HV06H	60V	HV06H06DG	HV06H06PG	HV06H06T	HV06H06X	—
	80V	HV06H08DG	HV06H08PG	HV06H08T	HV06H08X	RBHV06H08DG

* For Hi-Rel process flows, please refer to page 5-3 in the Databook.

Features

- ☐ HVCMOS® Technology
- ☐ Output voltages up to 80V
- ☐ Low power level shifting
- ☐ Shift register speed 8 MHz
- ☐ Latched data outputs
- ☐ Output polarity and blanking
- ☐ CMOS compatible inputs
- ☐ Forward and reverse shifting options

Absolute Maximum Ratings[1]

Supply voltage, V_{DD}		-0.5V to +15V
Supply voltage, V_{PP}		-0.5V to +80V
Logic input levels		-0.5V to V_{DD} +0.5V
Ground current[3]		3.0A
High voltage supply current[2]		2.6A
Continuous total power dissipation[3]	Ceramic	1900mW
	Plastic	1200mW
Operating temperature range	Ceramic	-40°C to +85°C
	Plastic	0°C to +70°C
Storage temperature range	-65°C to +150°C	

Notes:
1. All voltages are referenced to ground.
2. Connection to all power and ground pads is required. Duty cycle is limited by the total power dissipated in the package.
3. For operation above 25°C ambient derate linearly to 85°C at 15mW/°C.

General Description

The HV04H and HV06H are low voltage serial to high voltage parallel converters with push-pull outputs. These devices have been designed for use as drivers for AC-electroluminescent displays. They can also be used in any application requiring multiple output high voltage current sourcing and sinking capabilities such as driving plasma panels, vacuum fluorescent, or large matrix LCD displays.

These devices consist of a 64-bit shift register, 64 latches, and control logic to perform the polarity select and blanking of the outputs. HVout1 is connected to the first stage of the shift register through the polarity and blanking logic. Data is shifted through the shift register on the low to high transition of the clock. The HV04H shifts data in the counterclockwise direction when viewed from the top of the package and the HV06H shifts in the clockwise direction. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register (HVout64). Operation of the shift register is not affected by the $\overline{LE}$ (latch enable), $\overline{BL}$ (blanking), or the $\overline{POL}$ (polarity) inputs. Transfer of data from the shift register to the latch occurs when the $\overline{LE}$ (latch enable) is high. The data in the latch is stored when $\overline{LE}$ is low.

The HV04H and HV06H devices are ruggedized versions of our standard HV04 and HV06. They are designed to be used in circuits where ramping of the high voltage supply is not feasible. Care must be taken to limit the load capacitance and surge current in any particular application.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Typ	Max	Units	Conditions
I_{DD}	V_{DD} Supply Current				25	mA	f_{CLK} = 8MHz, f_{DATA} = 4MHz $\overline{LE}$ = LOW
I_{DDQ}	Quiescent V_{DD} Supply Current				0.25	mA	All V_{IN} = 0V or V_{DD}
I_{PP}	High Voltage Supply Current				0.50	mA	V_{PP} = 80V All outputs high
					0.50	mA	V_{PP} = 80V All outputs low
I_{IH}	High-Level Logic Input Current				10	µA	$V_{IH} = V_{DD}$
I_{IL}	Low-Level Logic Input Current		-10			µA	V_{IL} = 0V
V_{OH}	High-Level Output	HV_{OUT}	74			V	V_{PP} = 80V, IHV_{OUT} = -20mA
		Data Out	V_{DD} - 1V			V	ID_{OUT} = -100µA
V_{OL}	Low-Level Output	HV_{OUT}			6.0	V	V_{PP} = 80V, IHV_{OUT} = +10mA
		Data Out			1.0	V	ID_{OUT} = +100µA
V_{OC}	HV_{OUT} Clamp Voltage				V_{PP} + 1.5	V	I_{OL} = +10mA
					-1.5	V	I_{OL} = -20mA

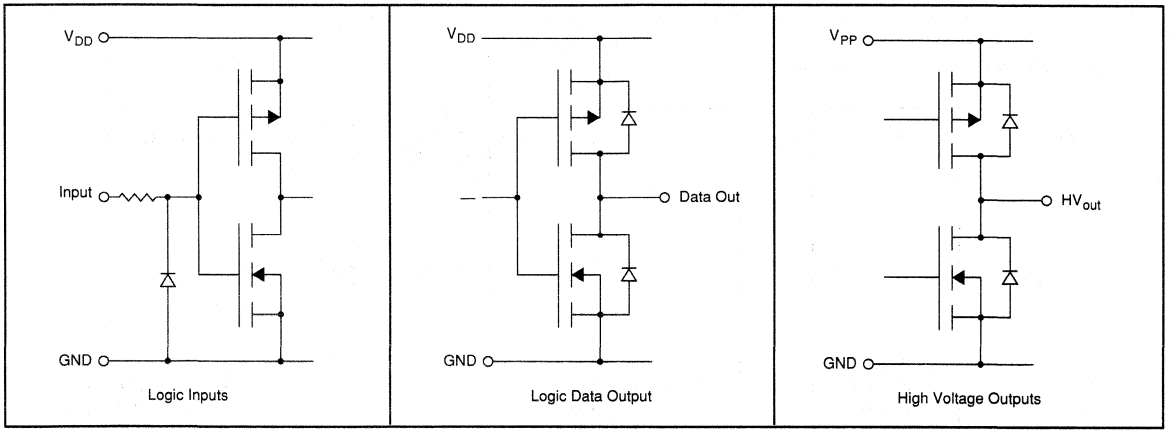
AC Characteristics

Symbol	Parameter	Min	Typ	Max	Units	Conditions
f_{CLK}	Clock Frequency			8	MHz	
t_W	Clock Width High or Low	62			ns	
t_{SU}	Data Setup Time Before Clock Rises	25			ns	
t_H	Data Hold Time After Clock Rises	10			ns	
t_{WLE}	Width of Latch Enable Pulse	62			ns	
t_{DLE}	$\overline{LE}$ Delay Time Rising Edge of Clock	25			ns	
t_{SLE}	$\overline{LE}$ Setup Time Before Rising Edge of Clock	30			ns	
t_{ON}, t_{OFF}	Time from Latch Enable to HV_{OUT}			50	ns	
t_{DHL}	Delay Time Clock to Data High to Low			100	ns	
t_{DLH}	Delay Time Clock to Data Low to High			100	ns	

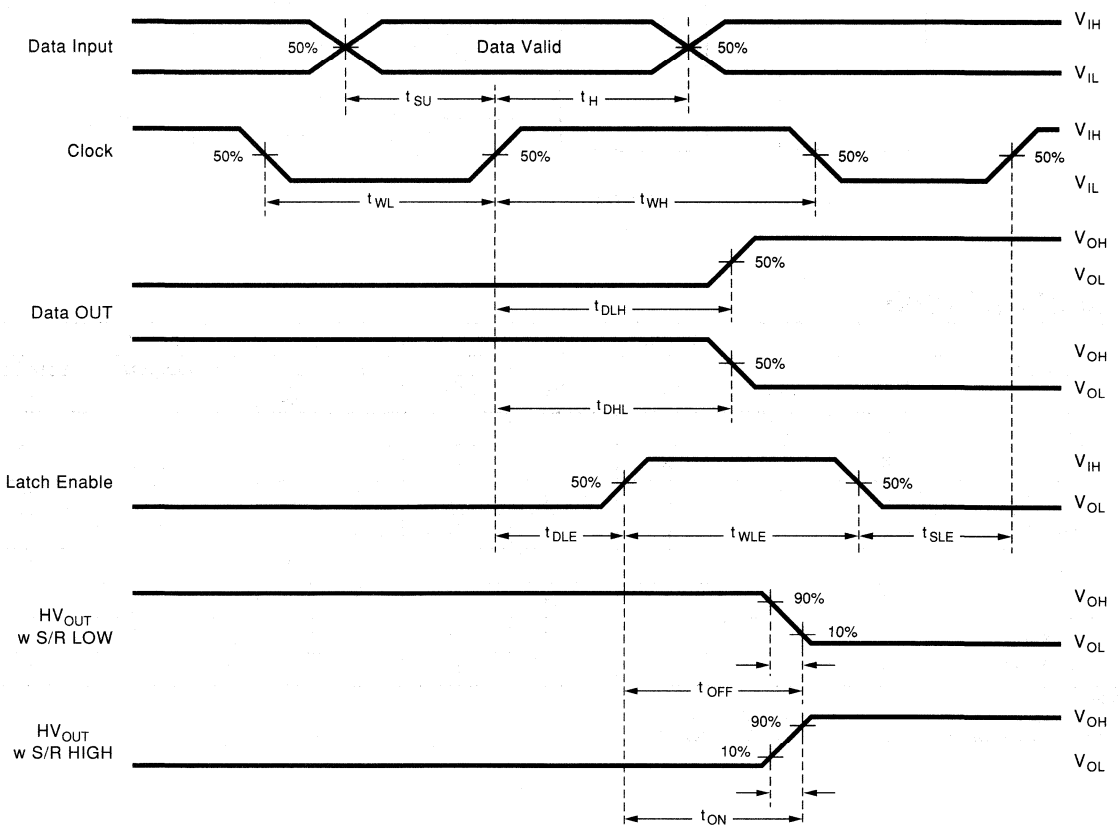
Recommended Operating Conditions

Symbol	Parameter	Min	Typ	Max	Units
V_{DD}	Logic supply voltage	10.8	12	13.2	V
V_{PP}	High voltage supply	-0.3		80	V
V_{IH}	High-level input voltage	V_{DD} - 2V		V_{DD}	V
V_{IL}	Low-level input voltage	0		2.0	V
T_A	Operating free-air temperature	-40		+85	°C

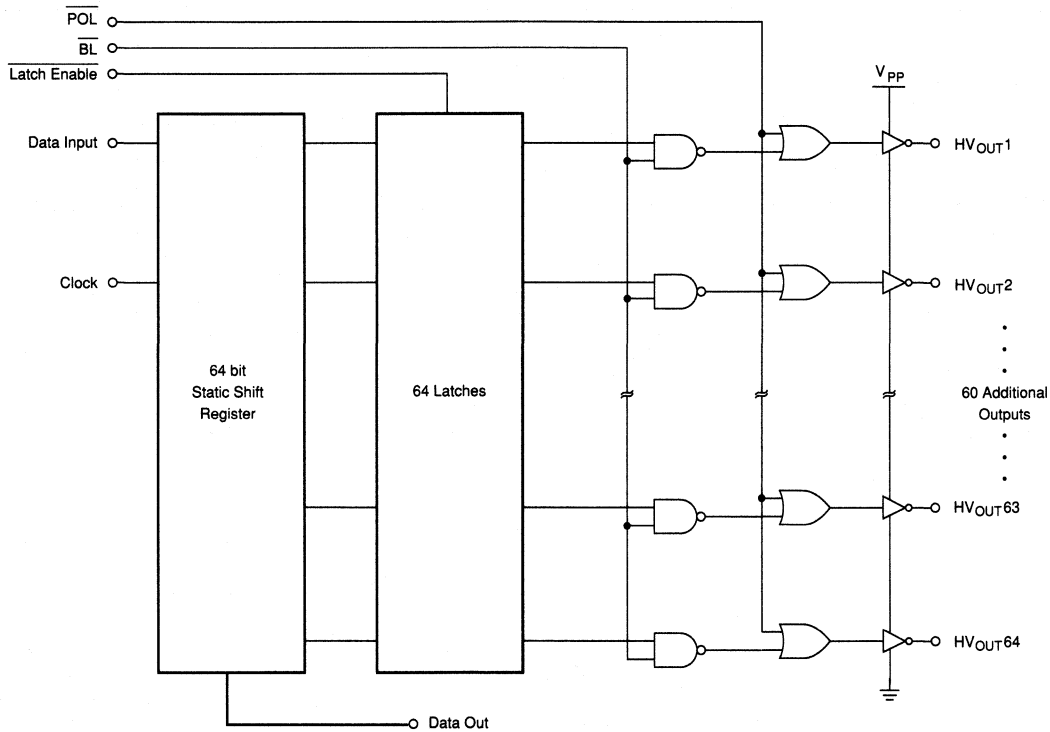
Input and Output Equivalent Circuits



Switching Waveforms



Functional Block Diagram



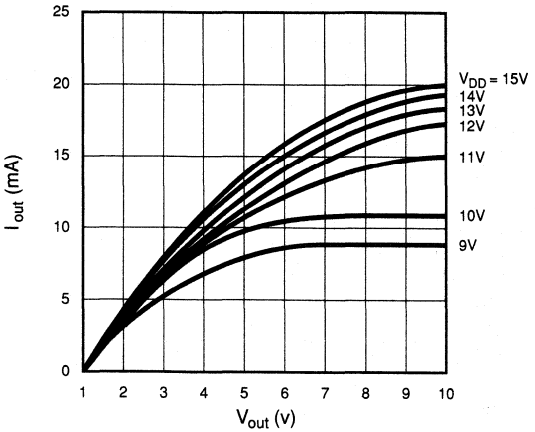
Function Table

Function	Inputs					Outputs		
	Data	CLK	$\overline{LE}$	$\overline{BL}$	$\overline{POL}$	Shift Reg 1 2...64	HV Outputs 1 2...64	Data Out *
All on	X	X	X	L	L	* *...*	H H...H	*
All off	X	X	X	L	H	* *...*	L L...L	*
Invert mode	X	X	L	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Load S/R	H or L	↑	L	H	H	H or L *...*	* *...*	*
Load Latches	X	H or L	↑	H	H	* *...*	* *...*	*
	X	H or L	↑	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Transparent Latch mode	L	↑	H	H	H	L *...*	L *...*	*
	H	↑	H	H	H	H *...*	H *...*	*

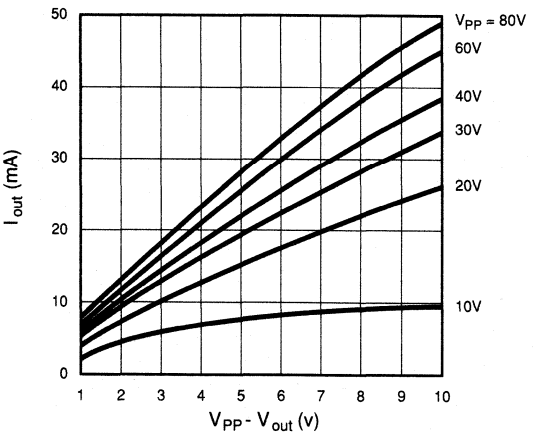
Notes:
H = high level, L = low level, X = irrelevant, ≠ = low-to-high transition.
* = dependent on previous stage's state before the last CLK or last $\overline{LE}$ high.

Typical Performance Curves

Typical HV04H/06H Sink Current @ 25°C



Typical HV04H/06H Source Current @ 25° C



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Pin Configurations

PG and DG Packages

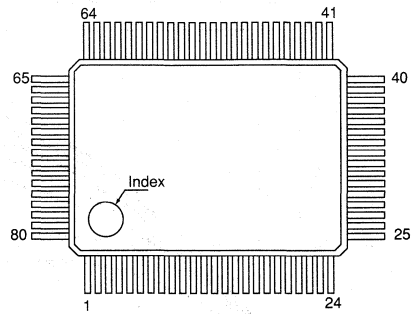
HV04H

Pin	Function	Pin	Function
1	GND	41	GND
2	V_{PP}	42	V_{PP}
3	HV_{OUT} 59	43	HV_{OUT} 23
4	HV_{OUT} 60	44	HV_{OUT} 24
5	HV_{OUT} 61	45	HV_{OUT} 25
6	HV_{OUT} 62	46	HV_{OUT} 26
7	HV_{OUT} 63	47	HV_{OUT} 27
8	HV_{OUT} 64	48	HV_{OUT} 28
9	$\overline{POL}$	49	HV_{OUT} 29
10	Data Out	50	HV_{OUT} 30
11	CLK	51	HV_{OUT} 31
12	GND	52	HV_{OUT} 32
13	V_{DD}	53	HV_{OUT} 33
14	$\overline{LE}$	54	HV_{OUT} 34
15	Data In	55	HV_{OUT} 35
16	$\overline{BL}$	56	HV_{OUT} 36
17	HV_{OUT} 1	57	HV_{OUT} 37
18	HV_{OUT} 2	58	HV_{OUT} 38
19	HV_{OUT} 3	59	HV_{OUT} 39
20	HV_{OUT} 4	60	HV_{OUT} 40
21	HV_{OUT} 5	61	HV_{OUT} 41
22	HV_{OUT} 6	62	HV_{OUT} 42
23	V_{PP}	63	V_{PP}
24	GND	64	GND
25	HV_{OUT} 7	65	HV_{OUT} 43
26	HV_{OUT} 8	66	HV_{OUT} 44
27	HV_{OUT} 9	67	HV_{OUT} 45
28	HV_{OUT} 10	68	HV_{OUT} 46
29	HV_{OUT} 11	69	HV_{OUT} 47
30	HV_{OUT} 12	70	HV_{OUT} 48
31	HV_{OUT} 13	71	HV_{OUT} 49
32	HV_{OUT} 14	72	HV_{OUT} 50
33	HV_{OUT} 15	73	HV_{OUT} 51
34	HV_{OUT} 16	74	HV_{OUT} 52
35	HV_{OUT} 17	75	HV_{OUT} 53
36	HV_{OUT} 18	76	HV_{OUT} 54
37	HV_{OUT} 19	77	HV_{OUT} 55
38	HV_{OUT} 20	78	HV_{OUT} 56
39	HV_{OUT} 21	79	HV_{OUT} 57
40	HV_{OUT} 22	80	HV_{OUT} 58

HV06H

Pin	Function	Pin	Function
1	GND	41	GND
2	V_{PP}	42	V_{PP}
3	HV_{OUT} 6	43	HV_{OUT} 42
4	HV_{OUT} 5	44	HV_{OUT} 41
5	HV_{OUT} 4	45	HV_{OUT} 40
6	HV_{OUT} 3	46	HV_{OUT} 39
7	HV_{OUT} 2	47	HV_{OUT} 38
8	HV_{OUT} 1	48	HV_{OUT} 37
9	$\overline{POL}$	49	HV_{OUT} 36
10	Data Out	50	HV_{OUT} 35
11	CLK	51	HV_{OUT} 34
12	GND	52	HV_{OUT} 33
13	V_{DD}	53	HV_{OUT} 32
14	$\overline{LE}$	54	HV_{OUT} 31
15	Data In	55	HV_{OUT} 30
16	$\overline{BL}$	56	HV_{OUT} 29
17	HV_{OUT} 64	57	HV_{OUT} 28
18	HV_{OUT} 63	58	HV_{OUT} 27
19	HV_{OUT} 62	59	HV_{OUT} 26
20	HV_{OUT} 61	60	HV_{OUT} 25
21	HV_{OUT} 60	61	HV_{OUT} 24
22	HV_{OUT} 59	62	HV_{OUT} 23
23	V_{PP}	63	V_{PP}
24	GND	64	GND
25	HV_{OUT} 58	65	HV_{OUT} 22
26	HV_{OUT} 57	66	HV_{OUT} 21
27	HV_{OUT} 56	67	HV_{OUT} 20
28	HV_{OUT} 55	68	HV_{OUT} 19
29	HV_{OUT} 54	69	HV_{OUT} 18
30	HV_{OUT} 53	70	HV_{OUT} 17
31	HV_{OUT} 52	71	HV_{OUT} 16
32	HV_{OUT} 51	72	HV_{OUT} 15
33	HV_{OUT} 50	73	HV_{OUT} 14
34	HV_{OUT} 49	74	HV_{OUT} 13
35	HV_{OUT} 48	75	HV_{OUT} 12
36	HV_{OUT} 47	76	HV_{OUT} 11
37	HV_{OUT} 46	77	HV_{OUT} 10
38	HV_{OUT} 45	78	HV_{OUT} 9
39	HV_{OUT} 44	79	HV_{OUT} 8
40	HV_{OUT} 43	80	HV_{OUT} 7

Package Outline



80-pin Gullwing Package

32–Channel Symmetric Row Drivers

Ordering Information

Device	Package Options			
	44 J-Lead Quad Ceramic Chip Carrier	44 J-Lead Quad Plastic Chip Carrier	Die in waffle pack	44 - Lead Ceramic J-Bend (MIL-STD-883 Processed*)
HV0923	HV0923DJ	HV0923PJ	HV0923X	RBHV0923DJ

* For Hi-Rel process flows, refer to page 5-3 of the Databook.

Features

- ☐ Processed with HVCMOS® technology
- ☐ Symmetric row drive (reduces latent imaging in ACTFEL displays)
- ☐ Output voltages up to 230V
- ☐ Very low-power level shifting
- ☐ Source/Sink current 200mA
- ☐ Shift Register Speed 4MHz
- ☐ Pin-programmable shift direction
- ☐ 44-lead plastic & ceramic surface-mount packages

General Description

The HV09 is a low-voltage serial to high-voltage parallel converter with push-pull outputs. It is especially suitable for use as a symmetric row driver in AC thin-film electroluminescent (ACTFEL) displays. The HV09 offers 32 output lines, a direction (DIR) pin to give CW or CCW shift register loading, output enable (OE), and polarity (POL) control. After DATA INPUT is entered (on the falling edge of CLOCK), a logic high will cause the output to swing to V_{PP} if POL is high, or to GND if POL is low.

Absolute Maximum Ratings

Supply voltage, V_{DD}[1]		-0.3V to +15V
Supply voltage, V_{PP}		-0.3V to +250V
Logic input levels		-0.3V to V_{DD} +0.3V
Ground currrent[2]		1.5A
Continuous total power dissipation[3]:	Ceramic	1500mW
	Plastic	1200mW
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. All voltages are referenced to GND.
2. Duty cycle is limited by the total power dissipated in the package.
3. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

Electrical Characteristics

(over recommended operating conditions of V_{DD} = 12V and V_{PP} = 230V unless noted)

DC Characteristics

Symbol	Parameter		Min	Max	Units	Conditions
I_{DD}	V_{DD} supply current			10	mA	f_{CLK} = 4MHz
				3	mA	f_{CLK} = 100kHz
I_{PPQ}	High voltage quiescent supply current			4	mA	1 output high[1]
				500	µA	All Outputs low
				500	µA	High Z state
I_{DDQ}	Quiescent V_{DD} supply current			100	µA	All V_{IN} = GND or V_{DD}
V_{OH}	High-level output	HV_{OUT}	200		V	I_O= -200mA
		Data out	11		V	I_O= -500µA
V_{OL}	Low-level output	HV_{OUT}		30	V	I_O= 200mA
		Data out		1	V	I_O= 500µA
I_{IH}	High-level logic input current			1	µA	V_{IH} = 12V
I_{IL}	Low-level logic input current			-1	µA	V_{IL} = 0V
V_{OC}	High voltage output clamp voltage			-2	V	I_O= -200mA

Note 1. The total number of ON outputs times the duty cycle must not exceed the allowable P_D.

AC Characteristics (V_{DD} = 12V, T_C = 25°C)

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock frequency		4	MHz	
t_W	Pulse duration clock high or low	125		ns	
t_{SUD}	Data set-up time before falling clock	100		ns	
t_{HD}	Data hold time after falling clock	100		ns	
t_{SUC}	Setup time clock low before V_{PP}↑ or GND↓	300		ns	
t_{SUE}	Setup time enable high before V_{PP}↑ or GND↓	300		ns	
t_{SUP}	Setup time polarity high or low before V_{PP}↑ or GND↓	300		ns	
t_{HC}	Hold time clock high after V_{PP}↑ or GND↓	500		ns	
t_{HE}	Hold time enable high after V_{PP}↑ or GND↓	300		ns	
t_{HP}	Hold time polarity high or low after V_{PP}↑ or GND↓	300		ns	
t_{DHL}	Delay time high to low level output from clock		150	ns	C_L = 30pF
t_{DLH}	Delay time low to high level output from clock		200	ns	C_L = 30pF
t_{THL}	Transition time high to low level serial output		200	ns	C_L = 30pF
t_{TLH}	Transition time low to high level serial output		100	ns	C_L = 30pF
t_{ONH}	High level turn-on time HV outputs from enable		1000	ns	I_O = -200 mA, V_{OH} =220V R_L = 500 Ω to 120V
t_{ONL}	Low level turn-on time HV outputs from enable		500	ns	I_O = 200 mA, V_{OH} =130V R_L = 500 Ω to 30V
t_{OFFH}	High level turn-off time HV outputs from enable		1000	ns	I_O = -200 mA, V_{OH} =220V R_L = 500 Ω to 120V
t_{OFFL}	Low level turn-off time HV outputs from enable		500	ns	I_O = 200 mA, V_{OH} =130V R_L = 500 Ω to 30V
	Slew rate, V_{PP} or GND		45	V/µs	With one active output driving a 4.7 nF load to V_{PP} or GND

Recommended Operating Conditions

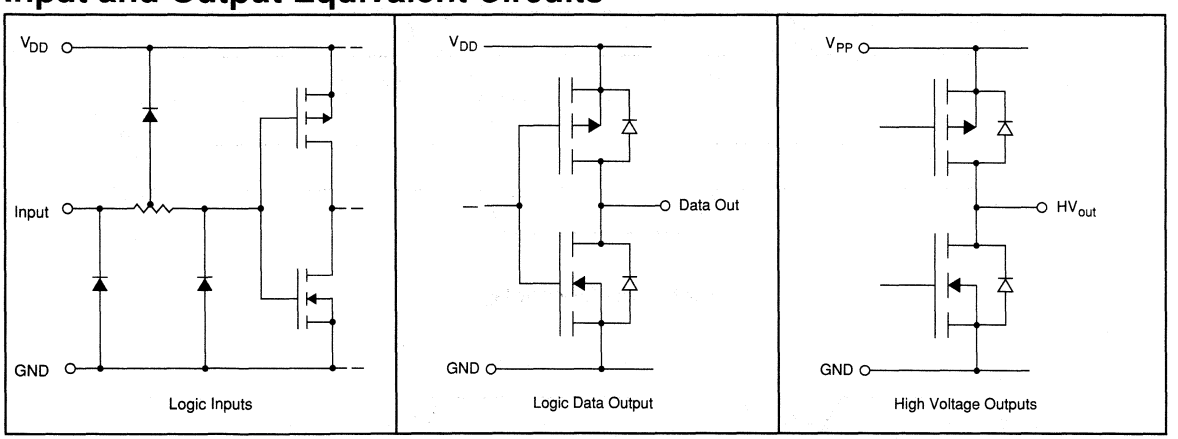
Symbol	Parameter		Min	Max	Units
V_{DD}	Logic supply voltage		10.8	13.2	V
V_{PP}	High voltage supply			230	V
V_{IH}	High-level input voltage	V_{DD} = 10.8V	8.1		V
		V_{DD} = 13.2V	9.9		
V_{IL}	Low-level input voltage	V_{DD} = 10.8V		2.7	V
		V_{DD} = 13.2V		3.3	
f_{CLK}	Clock frequency			4	MHz
T_A	Operating free-air temperature	Commercial	0	+70	°C
		Military Hi-Rel (RB)	-55	+125	°C

Note:
Power-up sequence should be the following:

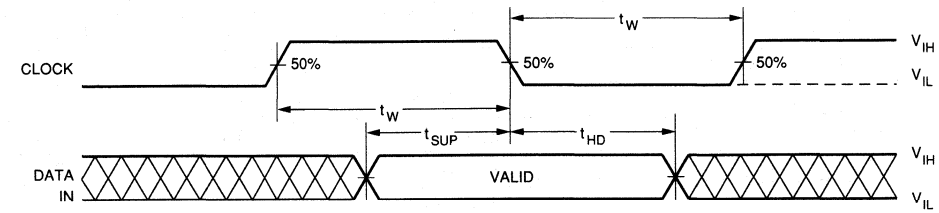
1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

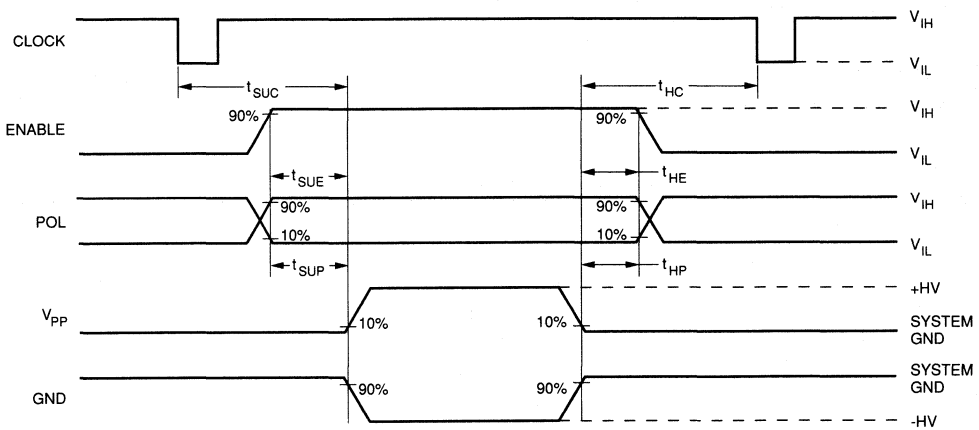
Input and Output Equivalent Circuits



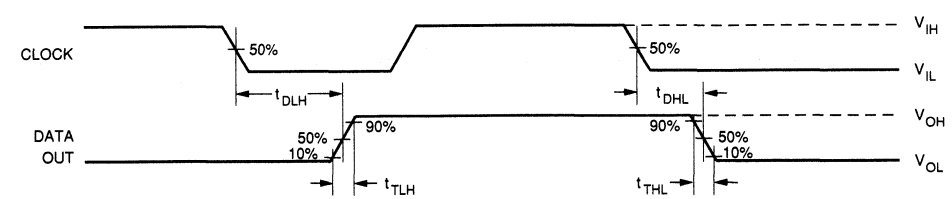
Switching Waveforms



Input Timing Voltage

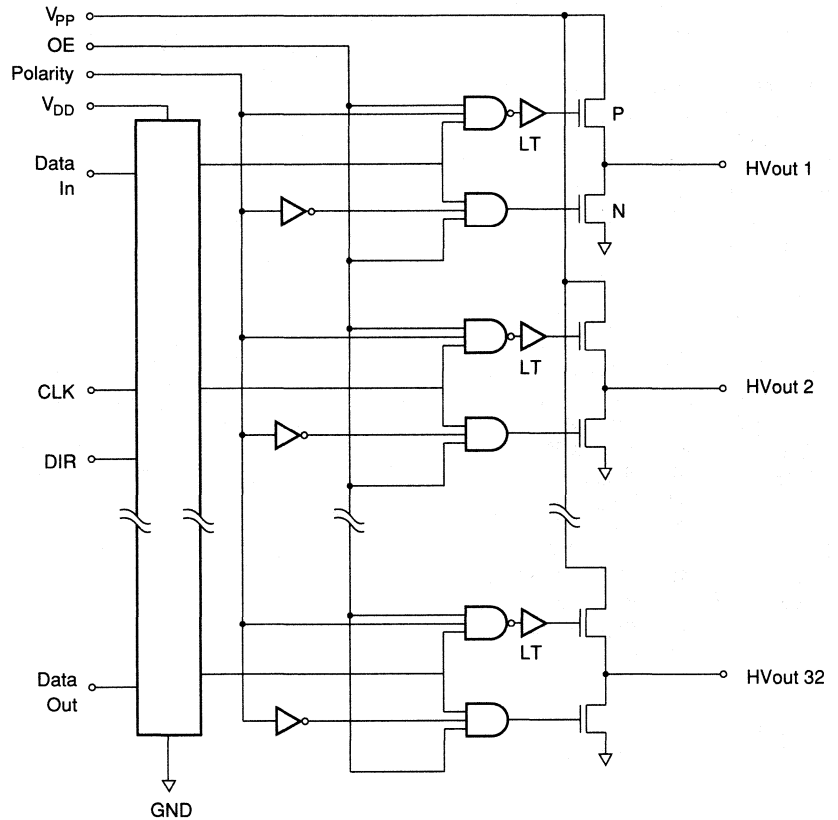


Control Input Timing Voltage



Voltage Waveforms for Propagation Delay Times,
Clock to Data Out

Functional Block Diagram



LT = Level Translator

Function Table

Outputs	Inputs					Outputs		
	CLK	DIR	Data	POL	OE	Shift Reg	HV Outputs	Data Out
O/P HIGH	X	X	H	H	H	*	H	
O/P OFF	X	X	L	H	H	*	HIGH-Z	*
O/P LOW	X	X	H	L	H	*	L	*
O/P OFF	X	X	L	L	H	*	HIGH-Z	*
All O/P OFF	X	X	X	X	L	*	All O/P HIGH-Z	*
Load S/R, set DIR	↓	L	X	X	X	$Q_n \rightarrow Q_{n+1}$	*	Q_{32}
	↓	H	X	X	X	$Q_n \rightarrow Q_{n-1}$	*	Q_1
I/O Relation	—	L	D_{IO} A	X	X	—	—	D_{IO} B
	—	H	D_{IO} B			—	—	D_{IO} A

Notes:

H = logic high level, L = logic low level, X = irrelevant, Ø = high-to-low transition.

$Q_1 = HV_{out}$ 1, $Q_n = HV_{out}$ (n), etc.

* = dependent on previous state and whether an O/P or S/R command occured.

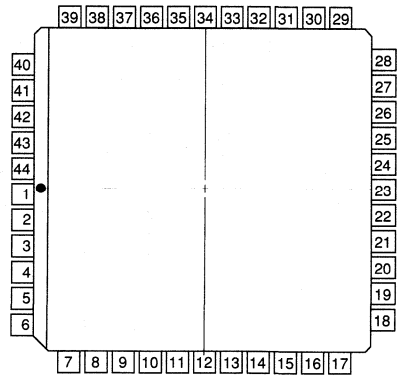
Pin Configurations

HV09
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 16/17	23	DIR
2	HV_{OUT} 15/18	24	V_{DD}
3	HV_{OUT} 14/19	25	Polarity
4	HV_{OUT} 13/20	26	Data I/O B
5	HV_{OUT} 12/21	27	GND
6	HV_{OUT} 11/22	28	V_{PP}
7	HV_{OUT} 10/23	29	HV_{OUT} 32/1
8	HV_{OUT} 9/24	30	HV_{OUT} 31/2
9	HV_{OUT} 8/25	31	HV_{OUT} 30/3
10	HV_{OUT} 7/26	32	HV_{OUT} 29/4
11	HV_{OUT} 6/27	33	HV_{OUT} 28/5
12	HV_{OUT} 5/28	34	HV_{OUT} 27/6
13	HV_{OUT} 4/29	35	HV_{OUT} 26/7
14	HV_{OUT} 3/30	36	HV_{OUT} 25/8
15	HV_{OUT} 2/31	37	HV_{OUT} 24/9
16	HV_{OUT} 1/32	38	HV_{OUT} 23/10
17	V_{PP}	39	HV_{OUT} 22/11
18	GND	40	HV_{OUT} 21/12
19	Data I/O A	41	HV_{OUT} 20/13
20	Output Enable	42	HV_{OUT} 19/14
21	Clock	43	HV_{OUT} 18/15
22	GND	44	HV_{OUT} 17/16

Note:
Pin designation for DIR = L/H
For DIR = H, Pin 1 is HV_{OUT} 16, for DIR = L Pin 1 is HV_{OUT} 17

Package Outline



top view

44-pin J-lead Package

4-Channel High Voltage Switch

Ordering Information

V_{PP}	V_{NN}	V_{SIG}	Order Number / Package		
			18-pin Ceramic Side-brazed DIP*	18-pin Plastic DIP	Die
+70V	-70V	110V P-P	HV1014C	HV1014P	HV1014X
+80V	-80V	130V P-P	HV1016C	HV1016P	HV1016X

* Consult factory for Cerdip and Ceramic LCC availability.

Features

- ☐ HVCMOS® Technology
- ☐ Up to 130V peak to peak switching capability
- ☐ Output On-resistance typically 25 ohms
- ☐ Low parasitic capacitances
- ☐ DC to 10MHz analog signal frequency
- ☐ 45 dB typical output off isolation at 5 MHz
- ☐ CMOS logic circuitry for low power and excellent noise immunity
- ☐ On-chip latch and chip select logic circuitry

General Description

This device is a 4-channel high-voltage integrated circuit (HVIC) intended for use in applications requiring high voltage switching controlled by low voltage signals; e.g., ultrasound imaging and printers. On-chip latches are provided for the data inputs. Using HVCMOS technology, this HVIC combines high voltage bi-lateral DMOS switches and low power CMOS logic to provide efficient control of high voltage analog signals.

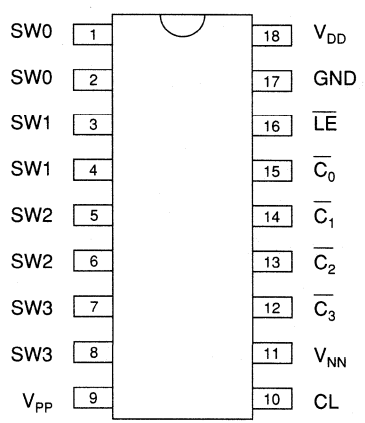
Absolute Maximum Ratings*

V_{DD} logic power supply voltage	-0.5V to +18V
V_{PP} - V_{NN} supply voltage	174V†
V_{PP} positive high voltage supply	-0.5V to +90V†
V_{NN} negative high voltage supply	+0.5V to -90V†
Logic input voltages	-0.5 to V_{DD} +0.3V
Analog signal range	V_{SIG} - V_{NN} = 0 to 144V†
Peak analog signal current/channel	3.0A
Storage temperature	-65°C to +150°C
Power dissipation	800mW

* Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied. Continuous operation of the device at the absolute rating level may affect device reliability.

† For HV1016.

Pin Configuration



top view

18-pin DIP

11

Electrical Characteristics

(over recommended operating conditions, V_{PP} = +80V, V_{NN} = -80V, and V_{DD} = 15V unless otherwise noted)*

DC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Switch (ON) Resistance	R_{ONS}		25		25	40		45	ohms	I_{SW} = 5mA
Switch (ON) Resistance	R_{ONS}		15		15	30		35	ohms	I_{SW} = 200mA
Switch (ON) Resistance	R_{ONS}		28		28	40		50	ohms	V_{PP} = +50V, V_{NN} = -50V, I_{SW} = 5mA
Switch (ON) Resistance	R_{ONS}		30		18	35		40	ohms	V_{PP} = +50V, V_{NN} = -50V, I_{SW} = 200mA
Switch (ON) Resistance Matching (0-3)	ΔR_{ONS}		15			15		15	%	V_{PP} = +50V, V_{NN} = -50V, I_{SW} = 5mA
Switch Off Leakage Per Switch	I_{SOL}		50		0.5	50		150	µA	V_{OUT} = V_{PP} -10V thru 10KΩ with 4 SWS in parallel
DC Offset Switch Off			500		100	500		500	mV	RL = 100K
DC Offset Switch On			500		100	500		500	mV	RL = 100K
Pole to Pole Switch Capacitance	C_{SW}		10		4.5	10		10	pF	DC Bias = 40V f = 1MHz
Logic Input Capacitance	C_{IN}				3.5				pF	
Pos. HV Supply Current	I_{PPQ}		200		50	200		200	µA	ALL SWS OFF
Neg. HV Supply Current	I_{NNQ}		-200		-50	-200		-200	µA	
Pos. HV Supply Current	I_{PPQ}				1.6	3.2			mA	1 SW ON
Neg. HV Supply Current	I_{NNQ}				-1.6	-3.2			mA	I_{SW} = 5mA
Pos. HV Supply Current	I_{PPQ}				1.2	2.4			mA	V_{PP} = +50V
Neg. HV Supply Current	I_{NNQ}				-1.2	-2.4			mA	V_{NN} = -50V, 1 SW ON, I_{SW} = 5mA
Switch Output Peak Current					2.5				A	V_{SIG} Duty Cycle ≤ 0.19 f = 10KHz
Logic Supply Average Current	I_{DD}				4				mA	Input Freq. = 3MHz
Logic Supply Quiescent Current	I_{DDQ}				10	500			µA	

AC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Data Hold Time After $\overline{LE}$ Rises	t_{HD}			5					ns	
Set Up Time Before $\overline{LE}$ Rises	t_{SD}			260					ns	
Time Width of $\overline{LE}$	t_{WLE}			300					ns	
Time Width of CL	t_{WCL}			5.0					µs	
Turn On Time	t_{ON}		5		2.5	5		5	µs	
Turn Off Time	t_{OFF}		10		5.0	10		10	µs	
Off Isolation	KO			-35	-45				dB	Signal Freq. = 5MHz
Switch Crosstalk	K_{CR}				-45				dB	Signal Freq. = 5MHz

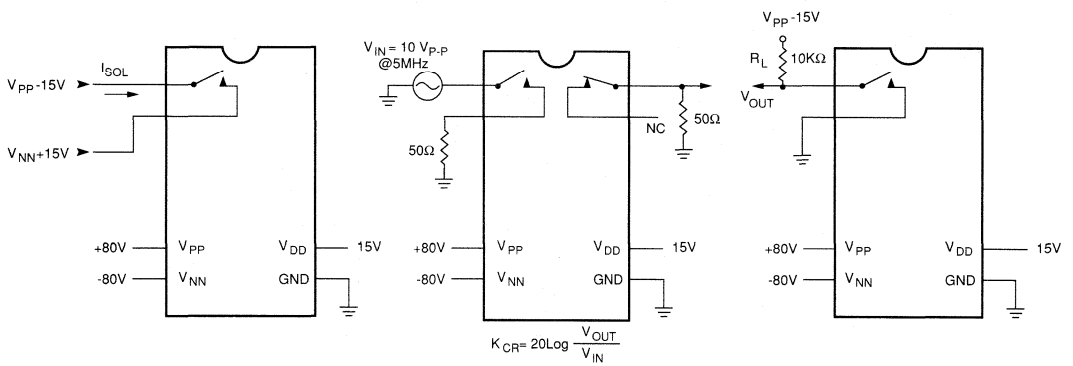
* For HV1016. For HV1014; V_{PP} = +70V, V_{NN} = -70V, and V_{DD} = 15V.

Recommended Operating Conditions

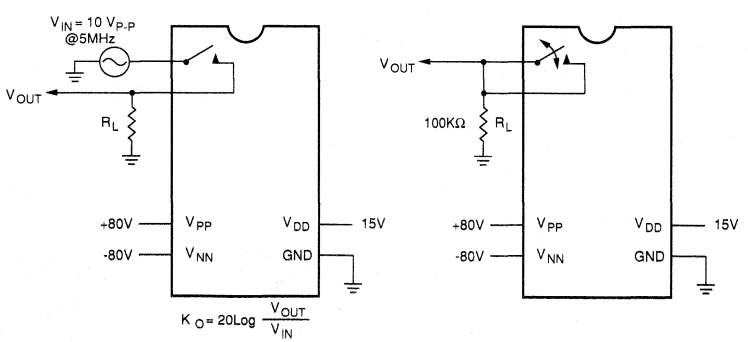
Symbol	Parameter	Device		Value
		HV1014	HV1016	
V_{DD}	Logic power supply voltage	X	X	+10V to +15.5V
V_{PP}	Positive high voltage supply	X		+50V to +70V
			X	+50V to +80V
V_{NN}	Negative high voltage supply	X		-50V to -70V
			X	-50V to -80V
V_{IH}	High level input voltage	X	X	V_{DD} -2V to V_{DD}
V_{IL}	Low level input voltage	X	X	0 to 2.0V
V_{SIG}	Analog signal voltage peak to peak	X	X	V_{NN} +15V to V_{PP} -15V
T_A	Operating free air-temperature	X	X	0° to 70°C

Note:
1. Power up/down sequence is arbitrary except GND must be powered-up first and powered -down last.
2. V_{SIG} must be $V_{NN} \leq V_{SIG} \leq V_{PP}$ or floating during power up/down transition.

Test Circuits

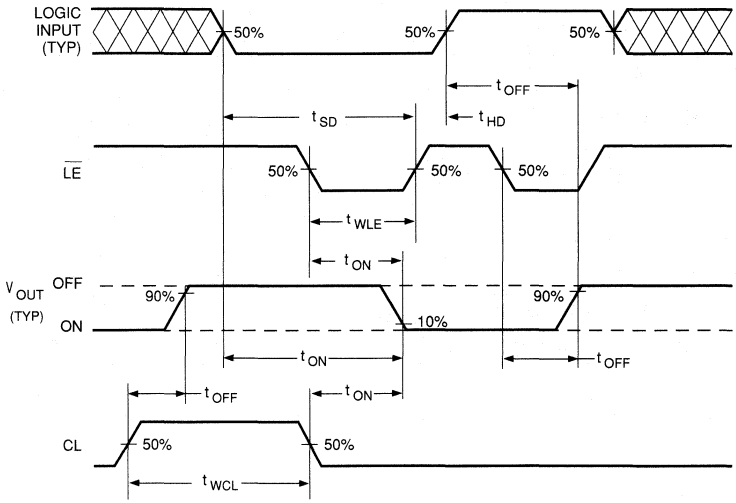


Switch OFF Leakage | Crosstalk | T_{ON} /T_{OFF}

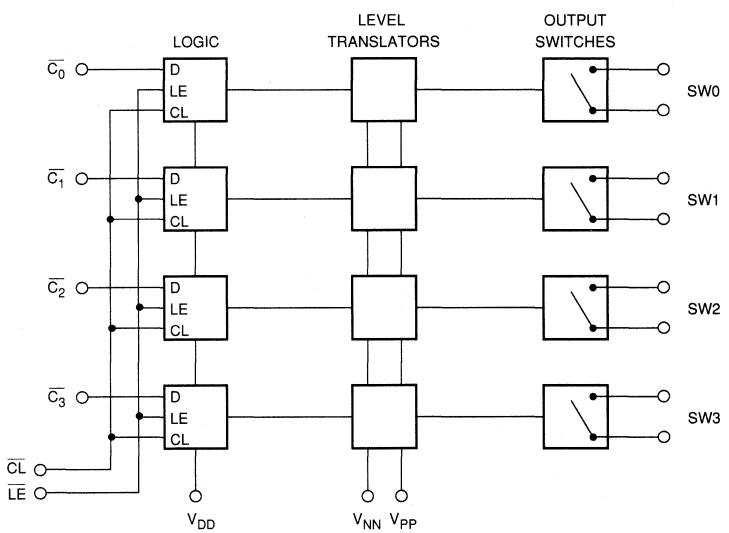


OFF Isolation | DC Offset ON/OFF

Logic Timing Waveforms



Logic Diagram



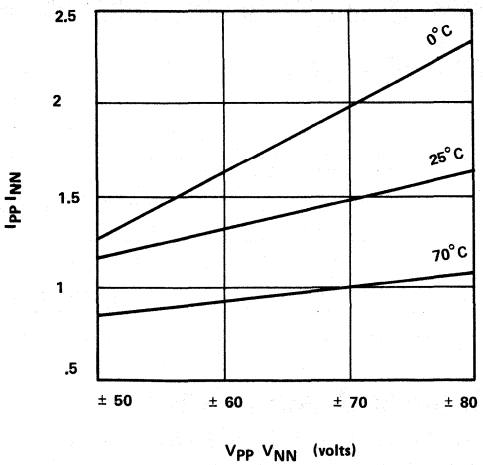
Truth Table

$\overline{C_0}$	$\overline{C1}$	$\overline{C2}$	$\overline{C3}$	$\overline{LE}$	CL	SW0	SW1	SW2	SW3
H				L	L	OFF			
L				L	L	ON			
	H			L	L		OFF		
	L			L	L		ON		
		H		L	L			OFF	
		L		L	L			ON	
			H	L	L				OFF
			L	L	L				ON
X	X	X	X	X	H	OFF	OFF	OFF	OFF
X	X	X	X	H	L	HOLD			

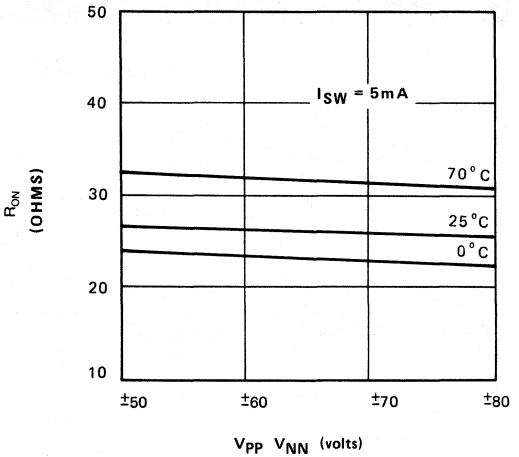
Notes: 1. The four switches operate independently.
2. The clear input overrides all other inputs.
3. The switches go to a state retaining their present condition at the rising edge of $\overline{LE}$. When $\overline{LE}$ is low, the switch control data flows through the latch.

Typical Performance Curves

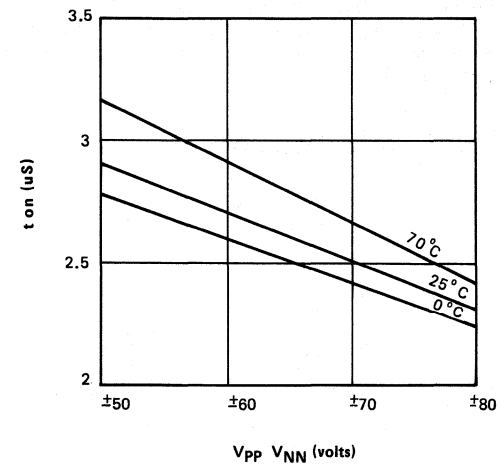
I_{PP} I_{NN} vs. V_{PP} V_{NN} (ONE SWITCH ON)



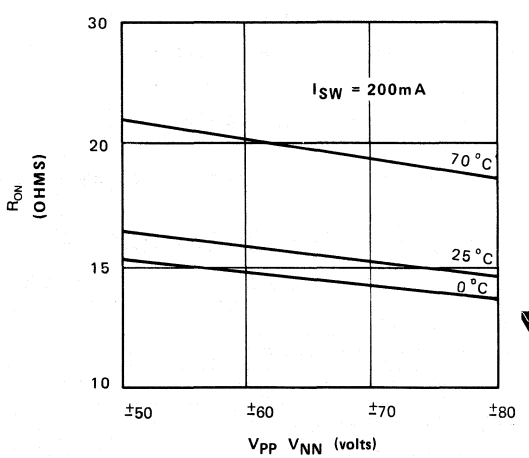
R_{ON} vs. V_{PP} V_{NN}



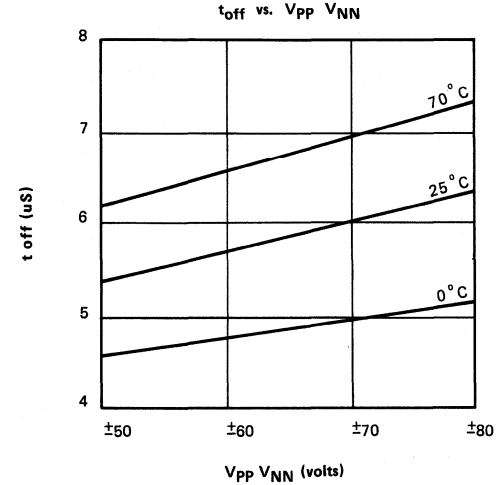
t on (uS) vs. V_{PP} V_{NN}



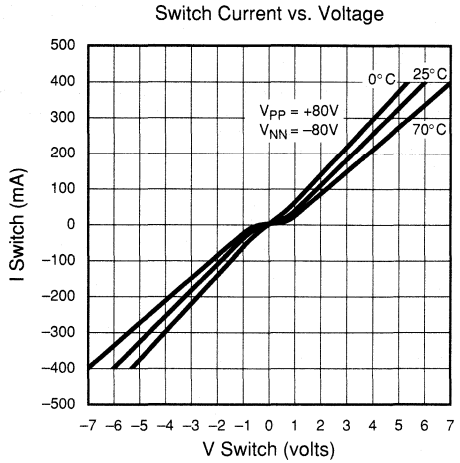
R_{ON} vs. V_{PP} V_{NN}



t_{off} vs. V_{PP} V_{NN}



Switch Current vs. Voltage



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8-Channel High Voltage Switch

Ordering Information

V_{PP}	V_{NN}	V_{SIG}	Package Options		
			18-pin Ceramic Side-brazed DIP*	18-pin Plastic DIP	Die in waffle pack
+70V	-70V	110V P-P	HV1214C	HV1214P	HV1214X
+80V	-80V	130V P-P	HV1216C	HV1216P	HV1216X

* Consult factory for Cerdip and Ceramic LCC availability.

Features

- ☐ HVCMOS® Technology
- ☐ Up to 130V peak to peak switching capability
- ☐ Output On-resistance typically 40 ohms
- ☐ Low parasitic capacitances
- ☐ DC to 10MHz analog signal frequency
- ☐ 45 dB typical output off isolation at 5 MHz
- ☐ CMOS logic circuitry for low power and excellent noise immunity
- ☐ On-chip shift register, latch and chip select logic circuitry

Absolute Maximum Ratings*

V_{DD} logic power supply voltage	-0.5V to +18V
V_{PP} - V_{NN} supply voltage	174V†
V_{PP} positive high voltage supply	-0.5V to +90V†
V_{NN} negative high voltage supply	+0.5V to -90V†
Logic input voltages	-0.5 to V_{DD} +0.3V
Analog signal range	V_{SIG} - V_{NN} = 0 to 144V†
Peak analog signal current/channel	1.5A
Storage temperature	-65°C to +150°C
Power dissipation	800mW

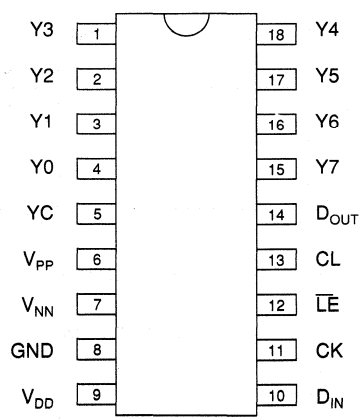
* Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied. Continuous operation of the device at the absolute rating level may affect device reliability.

† For HV1216

General Description

This device is an 8-channel high-voltage integrated circuit (HVIC) intended for use in applications requiring high voltage switching controlled by low voltage signals; e.g., ultrasound imaging and printers. Input data is shifted into an 8-bit shift register which can then be retained in an 8-bit latch. Using HVCMOS technology, this HVIC combines high voltage bi-lateral DMOS switches and low power CMOS logic to provide efficient control of high voltage analog signals.

Pin Configuration



top view

18-pin DIP

Electrical Characteristics

(over recommended operating conditions, V_{PP} = +80V, V_{NN} = -80V, and V_{DD} = 15V unless otherwise noted)*

DC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Switch (ON) Resistance	R_{ONS}		40		40	50		60	ohms	I_{SW} = 5mA
Switch (ON) Resistance	R_{ONS}		35		25	35		45	ohms	I_{SW} = 200mA
Switch (ON) Resistance	R_{ONS}		55		45	55		65	ohms	V_{PP} = +50V, V_{NN} = -50V I_{SW} = 5mA
Switch (ON) Resistance	R_{ONS}		40		25	40		50	ohms	V_{PP} = +50V, V_{NN} = -50V I_{SW} = 200mA
Switch (ON) Resistance Matching	ΔR_{ONS}		30		10	30		30	%	V_{PP} = +50V, V_{NN} = -50V, I_{SW} = 5mA
Switch Off Leakage Per Switch	I_{SOL}		50		0.5	50		150	µA	V_{OUT} = V_{PP} -10V thru 10KΩ with 8 SWS in parallel
DC Offset Switch Off			500		100	500		500	mV	RL = 100K
DC Offset Switch On			500		100	500		500	mV	RL = 100K
Pole to Pole Switch Capacitance	C_{SW}		10		4.5	10		10	pF	DC Bias = 40V f = 1MHz
Logic Input Capacitance	C_{IN}				3.5				pF	
Pos. HV Supply Current	I_{PPQ}		200		50	200		200	µA	ALL SWS OFF
Neg. HV Supply Current	I_{NNQ}		-200		-50	-200		-200	µA	
Pos. HV Supply Current	I_{PPQ}				0.8	1.6			mA	1 SWS ON
Neg. HV Supply Current	I_{NNQ}				-0.8	-1.6			mA	I_{SW} = 5mA
Pos. HV Supply Current	I_{PPQ}				0.6	1.2			mA	V_{PP} = +50V, V_{NN} = -50V
Neg. HV Supply Current	I_{NNQ}				-0.6	-1.2			mA	1 SW ON, I_{SW} = 5mA
Switch Output Peak Current					1.5				A	V_{SIG} Duty Cycle ≤0.1% f = 10KHz
Logic Supply Average Current	I_{DD}				4	6			mA	f_{CLK} = 3 MHz
Data Out Source Current	I_{SOR}	0.7		0.8	0.9		0.7		mA	V_{OUT} = V_{DD} -0.7V
Data Out Sink Current	I_{SINK}	0.7		0.8	0.9		0.7		mA	V_{OUT} = 0.7V
Logic Supply Quiesent Current	I_{DDQ}				10	500			µA	

AC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Set Up Time Before $\overline{LE}$ Rises	t_{SD}			260					ns	
Time Width of $\overline{LE}$	t_{WLE}			300					ns	
Clock Delay Time Data Out	t_{DO}				250	330			ns	
Turn On Time	t_{ON}		5		2.5	5		5	µs	
Turn Off Time	t_{OFF}		10		5.0	10		10	µs	
Time Width of CL	t_{WCL}			5					µs	
Off Isolation	KO			-35	-45				dB	f = 5MHz
Clock Frequency	f_{CLK}					3			MHz	50% Duty Cycle f_{DATA} = f_{CLK}/2
Set Up Time Data to Clock	t_{SU}			0					ns	
Hold Time Data from Clock	t_h			5					ns	
Switch Crosstalk	K_{CR}				-45				dB	Signal Freq = 5MHz

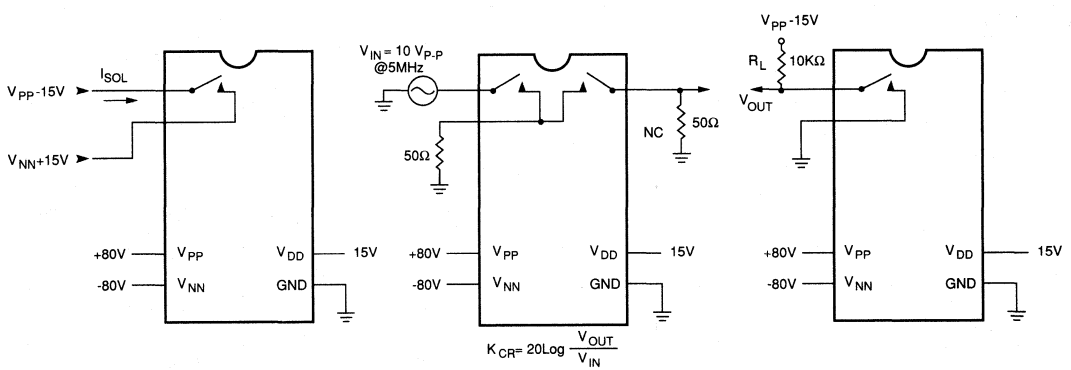
* For HV1216. For HV1214; V_{PP} = +70V, V_{NN} = -70V, and V_{DD} = 15V .

Recommended Operating Conditions

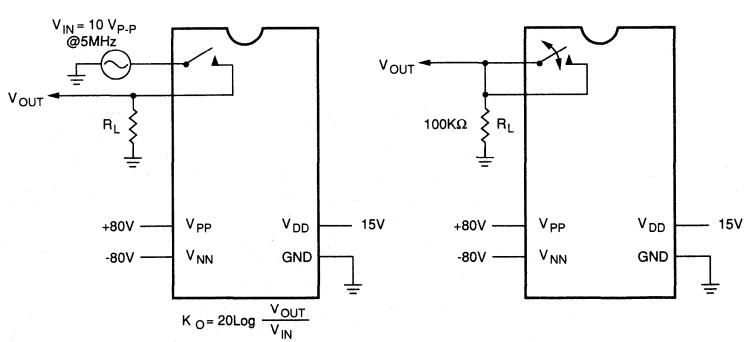
Symbol	Parameter	Device		Value
		HV1214	HV1216	
V_{DD}	Logic power supply voltage	X	X	+10V to +15.5V
V_{PP}	Positive high voltage supply	X		+50.0V to +70V
			X	+50.0V to +80V
V_{NN}	Negative high voltage supply	X		-50V to -70V
			X	-50V to -80V
V_{IH}	High level input voltage	X	X	V_{DD} -2V to V_{DD}
V_{IL}	Low-level input voltage	X	X	0 to 2.0V
V_{SIG}	Analog signal voltage peak to peak	X	X	V_{NN} +15V to V_{PP} -15V
T_A	Operating free air-temperature	X	X	0° to 70°C

Note:
1. Power up/down sequence is arbitrary except GND must be powered-up first and powered - down last.
2. V_{SIG} must be $V_{NN} \leq V_{SIG} \leq V_{PP}$ or floating during power up/down transition.

Test Circuits

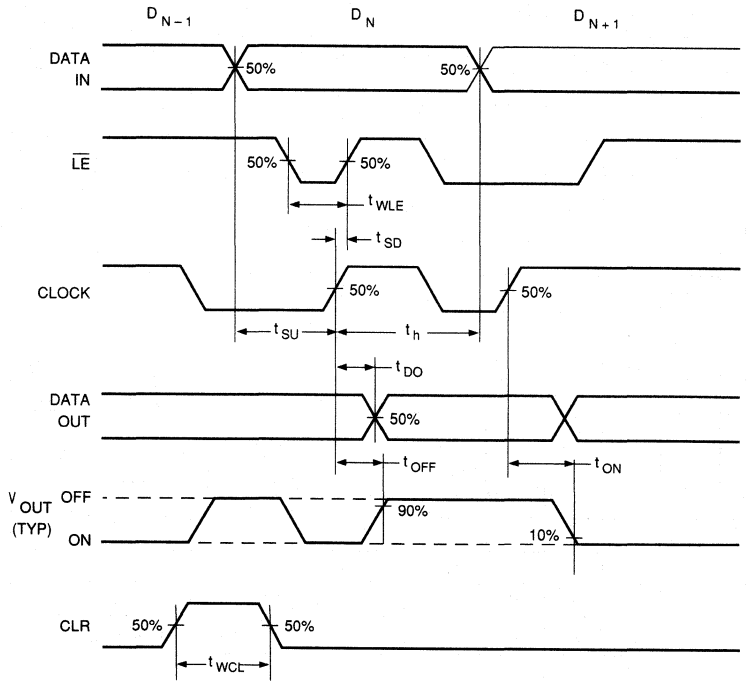


Switch OFF Leakage | Crosstalk | T_{ON} /T_{OFF}

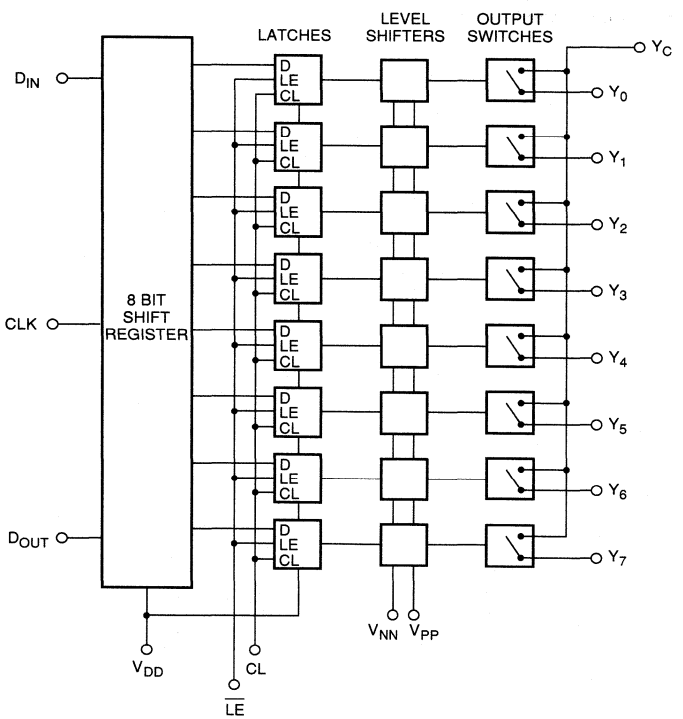


OFF Isolation | DC Offset ON/OFF

Logic Timing Waveform



Logic Diagram



Truth Table

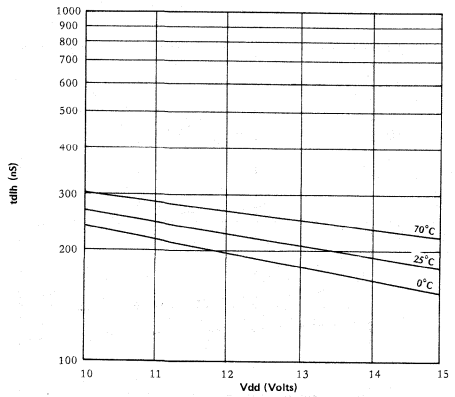
D_0	D_1	D_2	D_3	D_4	D_5	D_6	D_7	$\overline{LE}$	CL	Y_0	Y_1	Y_2	Y_3	Y_4	Y_5	Y_6	Y_7
L								L	L	OFF							
H								L	L	ON							
	L							L	L		OFF						
	H							L	L		ON						
		L						L	L			OFF					
		H						L	L			ON					
			L					L	L				OFF				
			H					L	L				ON				
				L				L	L					OFF			
				H				L	L					ON			
					L			L	L						OFF		
					H			L	L						ON		
						L		L	L							OFF	
						H		L	L							ON	
							L	L	L								OFF
							H	L	L								ON
X	X	X	X	X	X	X	X	X	H	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF
X	X	X	X	X	X	X	X	H	L	HOLD PREVIOUS STATE							

Notes:

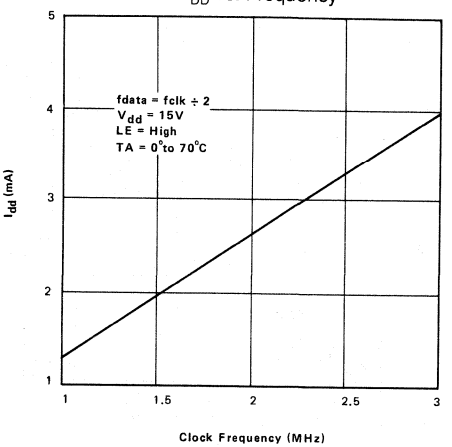
1. The eight switches operate independently, but connect to a common Z line.
2. Serial data is clocked in on the L→H transition of CK.
3. The clear input overrides all other inputs.
4. The switches go to a state retaining their present condition at the rising edge of $\overline{LE}$. When $\overline{LE}$ is low, the shift register data flows through the latch.
5. D_{OUT} is high when switch 7 is on
6. Shift register clocking has no effect on the switch states if $\overline{LE}$ is H.

Typical Performance Curves

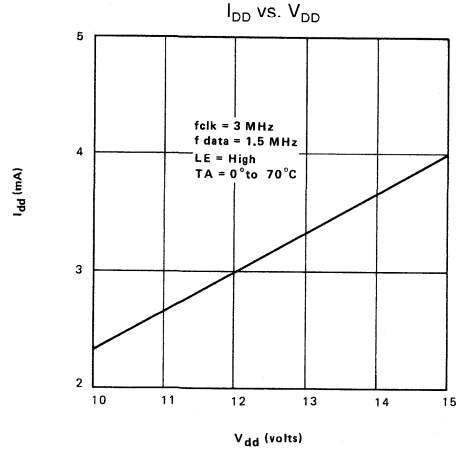
t_{dlh} vs. V_{DD}



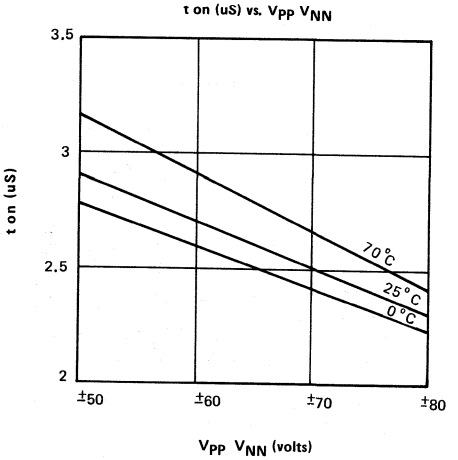
I_{DD} vs. Frequency



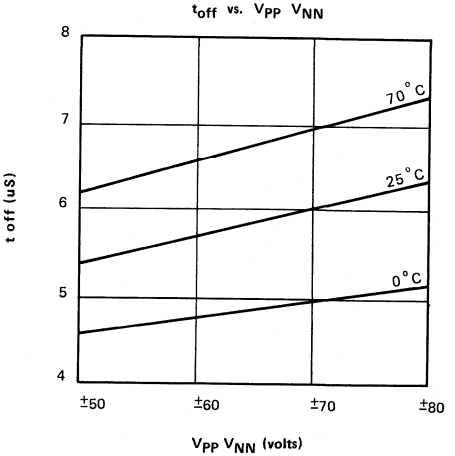
I_{DD} vs. V_{DD}



t on (uS) vs. V_{PP} V_{NN}



t_{off} vs. V_{PP} V_{NN}



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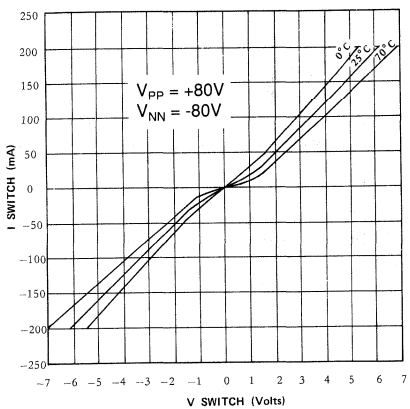
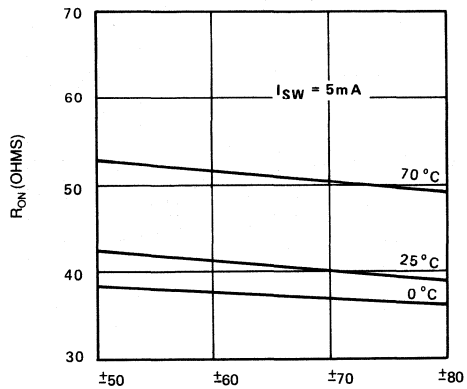
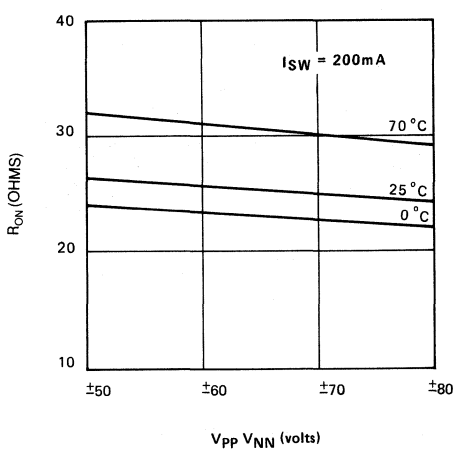
SWITCH CURRENT vs VOLTAGE



R_{ON} vs. V_{PP} V_{NN}



R_{ON} vs. V_{PP} V_{NN}



8-Channel High Voltage Switch with Decoded Switch Selection

Ordering Information

V_{PP}	V_{NN}	V_{SIG}	Package Options		
			20-pin Ceramic Side-brazed DIP	20-pin Plastic DIP	Die
+70V	-70V	110V P-P	HV1414C	HV1414P	HV1414X
+80V	-80V	130V P-P	HV1416C	HV1416P	HV1416X

* Consult factory for Cerdip and Ceramic LCC availability.

Features

- ☐ HVCMOS® Technology
- ☐ Up to 130V peak to peak switching capability
- ☐ Output On-resistance typically 40 ohms
- ☐ Low parasitic capacitances
- ☐ DC to 10MHz analog signal frequency
- ☐ 45 dB typical output off isolation at 5 MHz
- ☐ CMOS logic circuitry for low power and excellent noise immunity
- ☐ On-chip decode, latch and chip select logic circuitry

General Description

This device is an 8-channel high-voltage integrated circuit (HVIC), configured as a 1 of 8 decode function, intended for use in applications requiring high voltage switching controlled by low voltage signals; e.g., ultrasound imaging and printers. On-chip latches are provided for the decoded data.

The unique control logic on this device provides individual control of each switch, allowing more than one switch to be turned on at a time. The clear function turns off all switches simultaneously. The chip select inputs control the latches, holding the output stable while the address and data are changed. Using HVCMOS technology, this HVIC combines high voltage bi-lateral DMOS switches and low power CMOS logic to provide efficient control of high voltage analog signals.

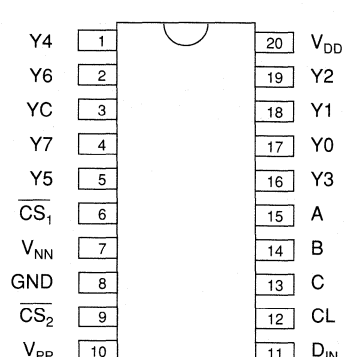
Absolute Maximum Ratings*

V_{DD} logic power supply voltage	-0.5V to +18V
V_{PP} - V_{NN} supply voltage	174V†
V_{PP} positive high voltage supply	-0.5V to +90V†
V_{NN} negative high voltage supply	+0.5V to -90V†
Logic input voltages	-0.5 to V_{DD} +0.3V
Analog signal range	V_{SIG} - V_{NN} = 0 to 144V†
Peak analog signal current/channel	1.5A
Storage temperature	-65°C to +150°C
Power dissipation	800mW

* Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied. Continuous operation of the device at the absolute rating level may affect device reliability.

† For HV1416

Pin Configuration



top view

20-pin DIP

Electrical Characteristics

(over recommended operating conditions, V_{PP} = +80V, V_{NN} = -80V, and V_{DD} = 15V unless otherwise noted)*

DC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Switch (ON) Resistance	R_{ONS}		50		40	50		60	ohms	I_{SW} = 5mA
Switch (ON) Resistance	R_{ONS}		35		25	35		45	ohms	I_{SW} = 200mA
Switch (ON) Resistance	R_{ONS}		55		45	55		65	ohms	V_{PP} = +50V, V_{NN} = -50V I_{SW} = 5mA
Switch (ON) Resistance	R_{ONS}		40		25	40		50	ohms	V_{PP} = +50V, V_{NN} = -50V I_{SW} = 200mA
Switch (ON) Resistance Matching	ΔR_{ONS}		30		10	30		30	%	V_{PP} = +50V, V_{NN} = -50V I_{SW} = 5mA
Switch Off Leakage Per Switch	I_{SOL}		50		0.5	50		150	µA	V_{OUT} = V_{PP} -10V thru 10KΩ with 8 SWS in parallel
DC Offset Switch Off			500		100	500		500	mV	RL = 100K
DC Offset Switch On			500		10	500		500	mV	RL = 100K
Pole to Pole Switch Capacitance	C_{SW}		10		4.5	10		10	pF	DC Bias = 40V f = 1MHz
Logic Input Capacitance	C_{IN}				3.5				pF	
Pos. HV Supply Current	I_{PPQ}		200		50	200		200	µA	ALL SWS OFF
Neg. HV Supply Current	I_{NNQ}		-200		-50	-200		-200	µA	
Pos. HV Supply Current	I_{PPQ}				0.8	1.6			mA	1 SW ON
Neg. HV Supply Current	I_{NNQ}				-0.8	-1.6			mA	I_{SW} = 5mA
Pos. HV Supply Current	I_{PPQ}				0.6	1.2			mA	V_{PP} = +50V
Neg. HV Supply Current	I_{NNQ}				-0.6	-1.2			mA	V_{NN} = -50V 1 SW ON, I_{SW} = 5mA
Switch Output Peak Current					1.5				A	V_{SIG} Duty Cycle ≤ 0.1% f = 10KHz
Logic Supply Average Current	I_{DD}				4				mA	Input Freq. = 3MHz @ 50% Duty Cycle
Logic Supply Quiescent Current	I_{DDQ}				10	500			µA	

AC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
D_{IN} Set Up Time Before $\overline{CS}$ Rises	t_{DSU}			260					ns	
Address Set Up Time Before $\overline{CS}$ Falls	t_{ASU}			120					ns	
Hold Time After $\overline{CS}$ Rises	t_h			35					ns	
Minimum Clear Pulse Width	t_{WCL}			5					µs	
Minimum Chip Select Low Pulse Width	t_{WCS}			300					ns	
Turn On Time	t_{ON}		5		2.5	5		5	µs	R_L = 10KΩ
Turn Off Time	t_{OFF}		10		5.0	10		10	µs	R_L = 10KΩ
Off Isolation	KO			-35	-45				dB	Signal Freq. = 5MHz
Switch Crosstalk	K_{CR}				-45				dB	Signal Freq. = 5MHz

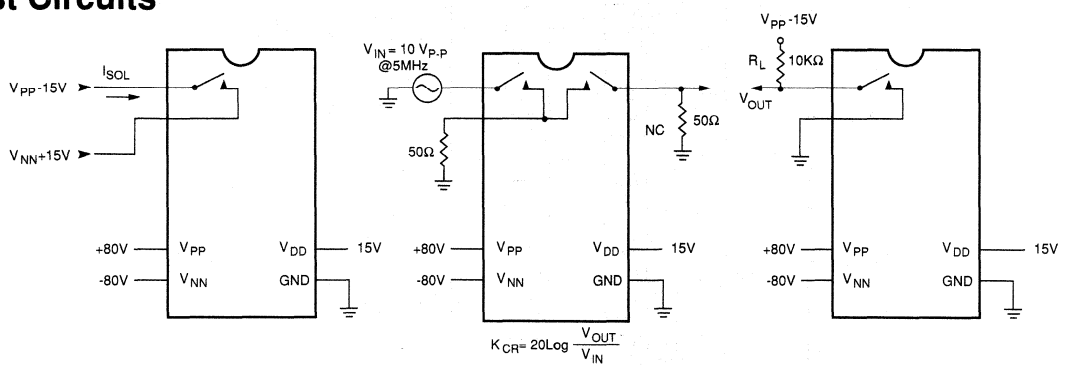
* For HV1416. For HV1414; V_{PP} = +70V, V_{NN} = -70V, and V_{DD} = 15V.

Recommended Operating Conditions

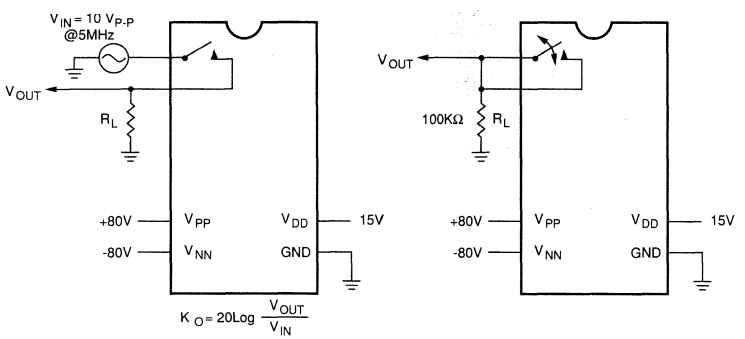
Symbol	Parameter	Device		Value
		HV1414	HV1416	
V_{DD}	Logic power supply voltage	X	X	+10.0V to +15.5V
V_{PP}	Positive high voltage supply	X		+50V to +70V
			X	+50V to +80V
		X		-50V to -70V
			X	-50V to -80V
V_{IH}	High level input voltage	X	X	V_{DD} -2V to V_{DD}
V_{IL}	Low-level input voltage	X	X	0 to 2.0V
V_{SIG}	Analog signal voltage peak to peak	X	X	V_{NN} +15V to V_{PP} -15V
T_A	Operating free air-temperature	X	X	0° to 70°C

Note:
1. Power up/down sequence is arbitrary except GND must be powered-up first and powered-down last.
2. V_{SIG} must be $V_{NN} \leq V_{SIG} \leq V_{PP}$ or floating during power up/down transition.

Test Circuits



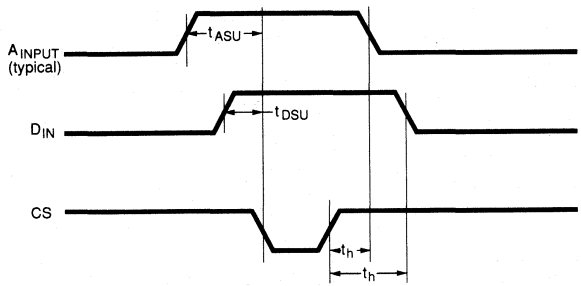
Switch OFF Leakage | Crosstalk | T_{ON} /T_{OFF}



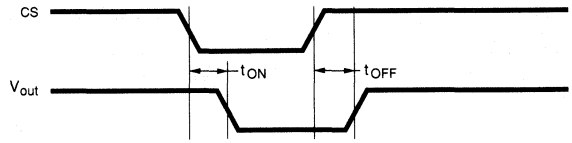
OFF Isolation | DC Offset ON/OFF

Switching Waveforms

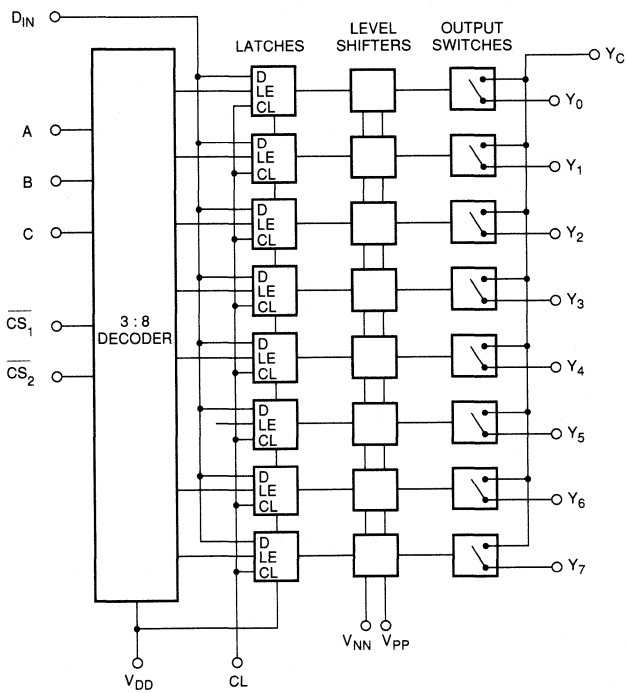
Logic Timing Waveforms



Output Timing Waveforms



Logic Diagram



Truth Table

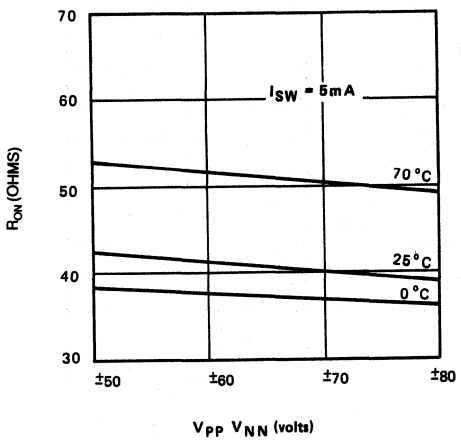
C	B	A	$\overline{CS_1}$	$\overline{CS_2}$	D_{IN}	CL	Y_0	Y_1	Y_2	Y_3	Y_4	Y_5	Y_6	Y_7
L	L	L	L	L	L	L	OFF							
L	L	L	L	L	H	L	ON							
L	L	H	L	L	L	L		OFF						
L	L	H	L	L	H	L		ON						
L	H	L	L	L	L	L			OFF					
L	H	L	L	L	H	L			ON					
L	H	H	L	L	L	L				OFF				
L	H	H	L	L	H	L				ON				
H	L	L	L	L	L	L					OFF			
H	L	L	L	L	H	L					ON			
H	L	H	L	L	L	L						OFF		
H	L	H	L	L	H	L						ON		
H	H	L	L	L	L	L							OFF	
H	H	L	L	L	H	L							ON	
H	H	H	L	L	L	L								OFF
H	H	H	L	L	H	L								ON
X	X	X	H	X	X	L	HOLDS PREVIOUS STATE							
X	X	X	X	H	X	L	HOLDS PREVIOUS STATE							
X	X	X	X	X	X	H	ALL OUTPUTS OFF							

Notes:

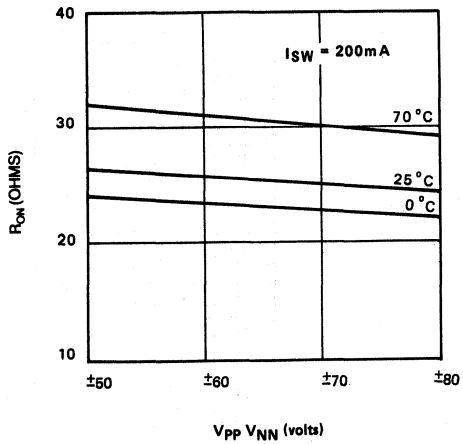
1. D_{IN} controls the switches through flow-through latches, which are clocked (enabled) by an 8-way decoder controlled by A, B, C, $\overline{CS_1}$, and $\overline{CS_2}$. Therefore, the latch for a particular switch goes into the HOLD state when any of the above inputs prevents selection. $\overline{CS_1}$ or $\overline{CS_2}$ can be used as an active LOW clock input.
2. Spurious clocking may occur if A, B, or C is changed with $\overline{CS_1}$ and $\overline{CS_2}$ both low.
3. The clear input CL overrides all other inputs.

Typical Performance Curves

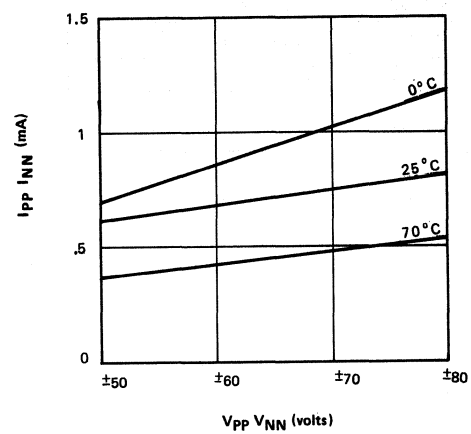
R_{ON} vs. V_{PP} V_{NN}



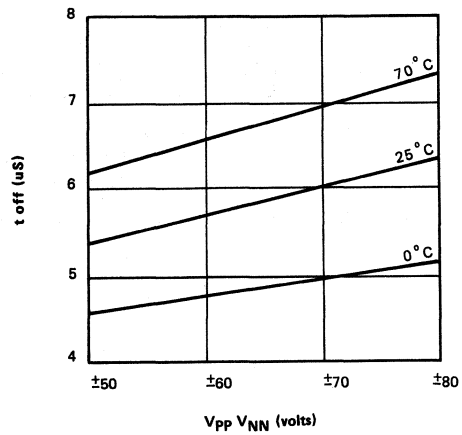
R_{ON} vs. V_{PP} V_{NN}



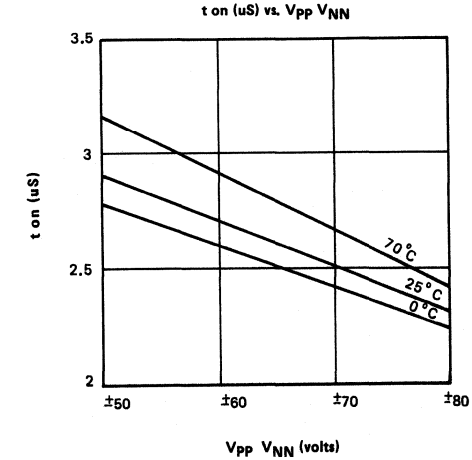
I_{PP} I_{NN} vs. V_{PP} V_{NN} (ONE SWITCH ON)



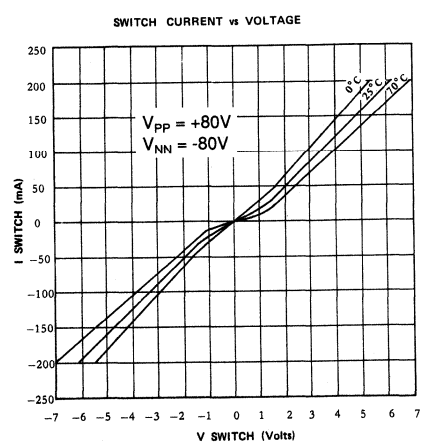
t_{off} vs. V_{PP} V_{NN}



t on (uS) vs. V_{PP} V_{NN}



SWITCH CURRENT vs VOLTAGE



1 of 8 Decode 8-Channel High Voltage Switch

Ordering Information

V_{PP}	V_{NN}	V_{SIG}	Package Options		
			20-pin Ceramic Side-brazed DIP	20-pin Plastic DIP	Die in waffle pack
+70V	-70V	110V P-P	HV1514C	HV1514P	HV1514X
+80V	-80V	130V P-P	HV1516C	HV1516P	HV1516X

*Consult factory for Cerdip and Ceramic LCC Availability.

Features

- ☐ HVCMOS® Technology
- ☐ Up to 130V peak to peak switching capability
- ☐ Output On-resistance typically 40 ohms
- ☐ Low parasitic capacitances
- ☐ DC to 10MHz analog signal frequency
- ☐ 45 dB typical output off isolation at 5 MHz
- ☐ CMOS logic circuitry for low power and excellent noise immunity
- ☐ On-chip decode, latch and chip select logic circuitry

Absolute Maximum Ratings*

V_{DD} logic power supply voltage	-0.5V to +18V
V_{PP} - V_{NN} supply voltage	174V†
V_{PP} positive high voltage supply	-0.5V to +90V†
V_{NN} negative high voltage supply	+0.5V to -90V†
Logic input voltages	-0.5 to V_{DD} +0.3V
Analog signal range	V_{SIG} - V_{NN} = 0 to 144V
Peak analog signal current/channel	1.5A†
Storage temperature	-65°C to +150°C
Power dissipation	800mW

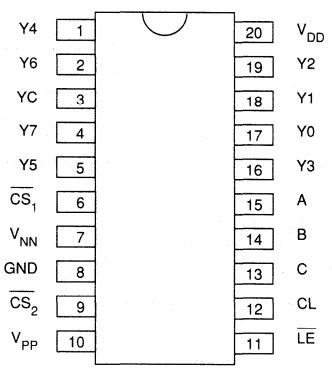
* Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied. Continuous operation of the device at the absolute rating level may affect device reliability.

† For HV1516

General Description

This device is an 8-channel high-voltage integrated circuit (HVIC), configured as a 1 of 8 decode functions, intended for use in applications requiring high voltage switching controlled by low voltage signals; e.g., ultrasound imaging and printers. ON-chip latches are provided for the decoded data. Using HVCMOS technology, this HVIC combines high voltage bi-lateral DMOS switches and low power CMOS logic to provide efficient control of high voltage analog signals.

Pin Configuration



top view

20-pin DIP

Electrical Characteristics

(over recommended operating conditions, V_{PP} = +80V, V_{NN} = -80V, and V_{DD} = 15V unless otherwise noted)*

DC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Switch (ON) Resistance	R_{ONS}		50		40	50		60	ohms	I_{SW} = 5mA
Switch (ON) Resistance	R_{ONS}		35		25	35		45	ohms	I_{SW} = 200mA
Switch (ON) Resistance	R_{ONS}		55		45	55		65	ohms	V_{PP} = +50V, V_{NN} = -50V I_{SW} = 5mA
Switch (ON) Resistance	R_{ONS}		40		25	40		50	ohms	V_{PP} = +50V, V_{NN} = -50V I_{SW} = 200mA
Switch (ON) Resistance Matching x and y (0-3)	ΔR_{ONS}		30		10	30		30	%	I_{SW} = 5mA V_{PP} = +50V, V_{NN} = -50V
Switch Off Leakage Per Switch	I_{SOL}		50		0.5	50		150	µA	V_{OUT} = V_{PP} -10V thru 10KΩ with 8 SWS in parallel
DC Offset Switch Off			500		100	500		500	mV	R_L = 100K
DC Offset Switch On			500		100	500		500	mV	R_L = 100K
Pole to Pole Switch Capacitance	C_{SW}		10		4.5	10		10	pF	DC Bias = 40V f = 1MHz
Logic Input Capacitance	C_{IN}				3.5				pF	
Pos. HV Supply Current	I_{PPQ}		200		50	200		200	µA	ALL SWS OFF
Neg. HV Supply Current	I_{NNQ}		-200		-50	-200		-200	µA	
Pos. HV Supply Current	I_{PPQ}				0.8	1.6			mA	1 SW ON
Neg. HV Supply Current	I_{NNQ}				-0.8	-1.6			mA	I_{SW} = 5mA
Pos. HV Supply Current	I_{PPQ}				0.6	1.2			mA	V_{PP} = +50V
Neg. HV Supply Current	I_{NNQ}				-0.6	-1.2			mA	V_{NN} = -50V 1 SW ON, I_{SW} = 5mA
Switch Output Peak Current					1.5				A	V_{SIG} Duty Cycle ≤0.1% f = 10KHz
Logic Supply Average Current	I_{DD}				4				mA	Input Freq. = 3MHz
Logic Supply Quiescent Current	I_{DDQ}				10	500			µA	

AC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Data Hold Time After $\overline{LE}$ Rises	t_{HD}			5					ns	
Set Up Time Before $\overline{LE}$ Rises	t_{SD}			260					ns	
Time Width of $\overline{LE}$	t_{WLE}			300					ns	
Time Width of CL	t_{WCL}			5					µs	
Turn On Time	t_{ON}		5		2.5	5		5	µs	R_L = 10KΩ
Turn Off Time	t_{OFF}		10		5.0	10		10	µs	R_L = 10KΩ
Off Isolation	KO			-35	-45				dB	Signal Freq. = 5MHz
Switch Crosstalk	K_{CR}				-45				dB	Signal Freq. = 5MHz

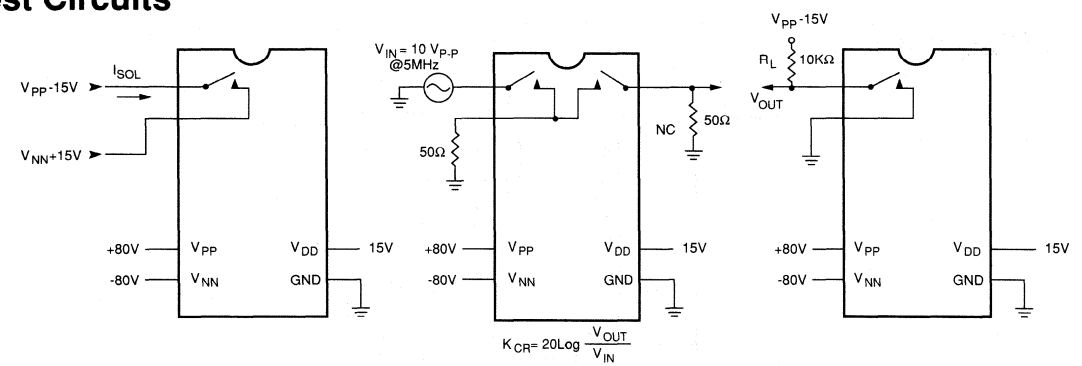
* For HV1516. For HV1514; V_{PP} = +70V, V_{NN} = -70V, and V_{DD} = 15V.

Recommended Operating Conditions

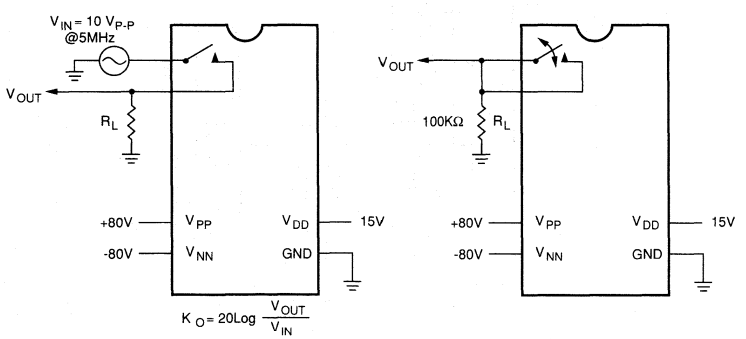
Symbol	Parameter	Device		Value
		HV1514	HV1516	
V_{DD}	Logic power supply voltage	X	X	+10.0V to +15.5V
V_{PP}	Positive high voltage supply	X		+50V to +70V
			X	+50V to +80V
V_{NN}	Negative high voltage supply	X		-50V to -70V
			X	-50V to -80V
V_{IH}	High level input voltage	X	X	V_{DD} -2V to V_{DD}
V_{IL}	Low-level input voltage	X	X	0 to 2.0V
V_{SIG}	Analog signal voltage peak to peak	X	X	V_{NN} +15V to V_{PP} -15V
T_A	Operating free air-temperature	X	X	0° to 70°C

Note:
1. Power up/down sequence is arbitrary except GND must be powered-up first and powered-down last.
2. V_{SIG} must be $V_{NN} \leq V_{SIG} \leq V_{PP}$ or floating during power up/down transition.

Test Circuits

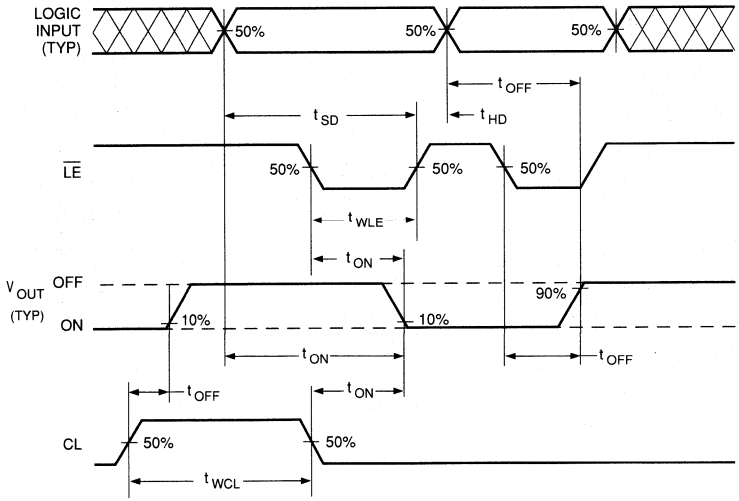


Switch OFF Leakage | Crosstalk | T_{ON} /T_{OFF}

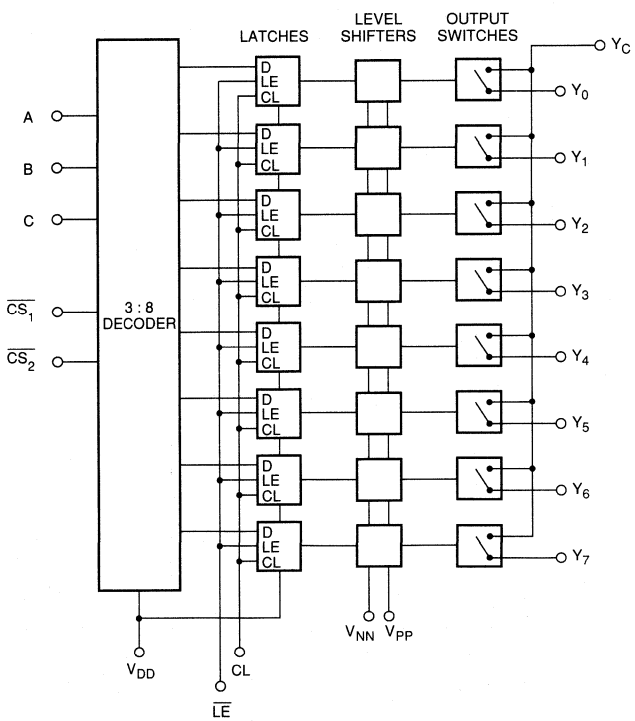


OFF Isolation | DC Offset ON/OFF

Logic Timing Waveforms



Logic Diagram



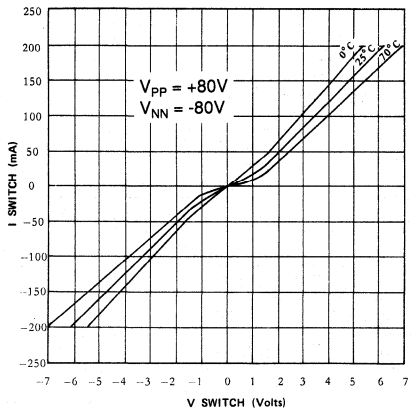
Truth Table

C	B	A	$\overline{CS_1}$	$\overline{CS_2}$	$\overline{LE}$	CL	Y0	Y1	Y2	Y3	Y4	Y5	Y6	Y7
L	L	L	L	L	L	L	ON							
L	L	H	L	L	L	L		ON						
L	H	L	L	L	L	L			ON					
L	H	H	L	L	L	L				ON				
H	L	L	L	L	L	L					ON			
H	L	H	L	L	L	L						ON		
H	H	L	L	L	L	L							ON	
H	H	H	L	L	L	L								ON
X	X	X	H	X	L	L	ALL OUTPUTS OFF							
X	X	X	X	H	L	L	ALL OUTPUTS OFF							
X	X	X	X	X	X	L	ALL OUTPUTS OFF							
X	X	X	X	X	H	L	HOLDS PREVIOUS STATE							

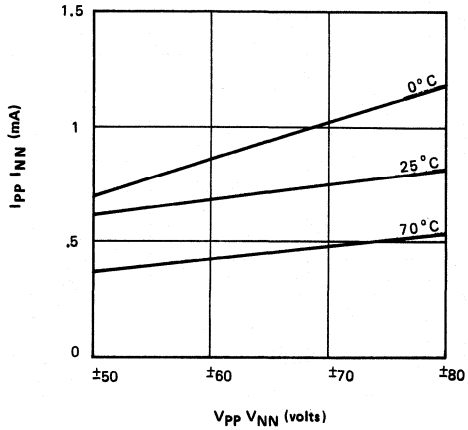
Notes:
1. Address data at A, $\overline{B}$, C cause on of the eight switches to be selected for connection to the common bus C.
2. The clear input CL overrides all other inputs.
3. Since the latch follows the decoder, only the CL input matters when $\overline{LE}$ is H.
4. The switches go to a state retaing their present condition at the rising edge of $\overline{LE}$. When $\overline{LE}$ is low, the decoded selection address information flows through the latch.

Typical Performance Curves

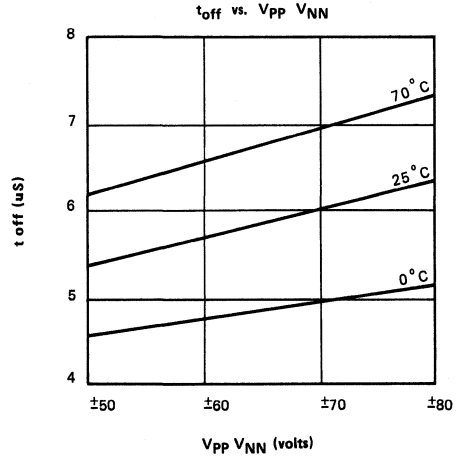
SWITCH CURRENT vs VOLTAGE



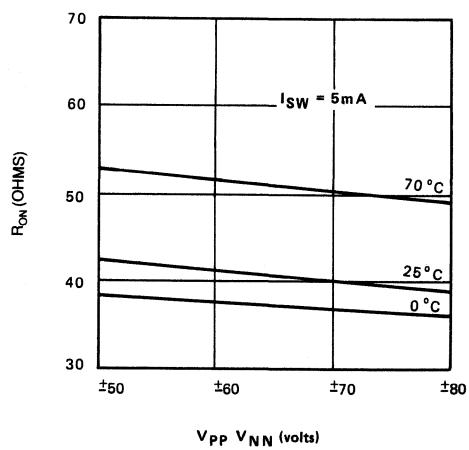
I_{PP} I_{NN} vs. V_{PP} V_{NN} (ONE SWITCH ON)



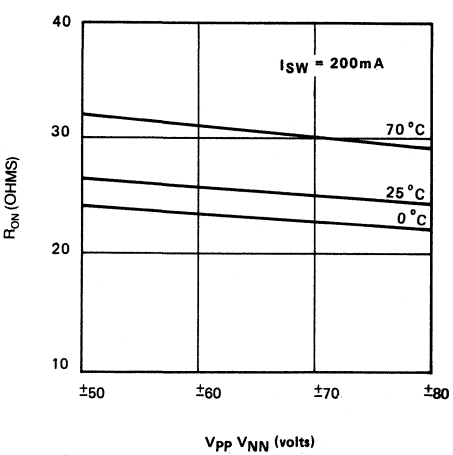
t_{off} vs. V_{PP} V_{NN}



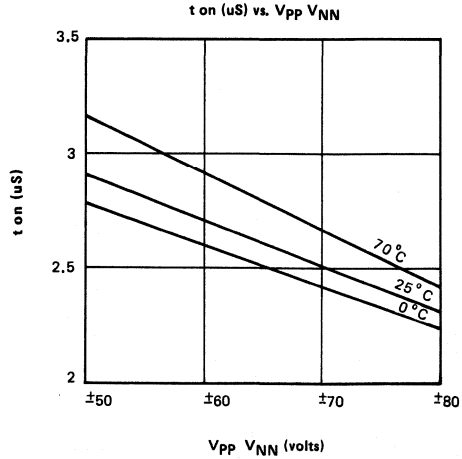
R_{ON} vs. V_{PP} V_{NN}



R_{ON} vs. V_{PP} V_{NN}



t on (uS) vs. V_{PP} V_{NN}



8-Channel High Voltage Switch

Ordering Information

V_{PP}	V_{NN}	V_{SIG}	Package Options				
			24-pin Ceramic Side-brazed DIP*	Die	36-pin Leaded Ceramic Chip Carrier*	24-pin Plastic DIP	28-lead Plastic Chip Carrier
+70V	-70V	110V P-P	HV1614C	HV1614X	HV1614CS	HV1614P	HV1614PJ
+80V	-80V	130V P-P	HV1616C	HV1616X	HV1616CS	HV1616P	HV1616PJ

* Consult factory for Cerdip and Ceramic LCC availability.

Features

- ☐ HVCMOS® technology
- ☐ Up to 130V peak to peak switching capability
- ☐ Output On-resistance typically 40 ohms
- ☐ Low parasitic capacitances
- ☐ DC to 10MHz analog signal frequency
- ☐ 45 dB typical output off isolation at 5 MHz
- ☐ CMOS logic circuitry for low power and excellent noise immunity
- ☐ On-chip shift register, latch and chip select logic circuitry
- ☐ Surface mount package available

General Description

This device is an 8-channel high-voltage integrated circuit (HVIC) intended for use in applications requiring high voltage switching controlled by low voltage signals; e.g., ultrasound imaging and printers. Input data is shifted into an 8-bit shift register which can then be retained in an 8-bit latch. Using HVCMOS technology, this HVIC combines high voltage bi-lateral DMOS switches and low power CMOS logic to provide efficient control of high voltage analog signals.

Absolute Maximum Ratings*

V_{DD} Logic power supply voltage	-0.5V to +18V
V_{PP} - V_{NN} supply voltage	174V†
V_{PP} Positive high voltage supply	-0.5V to +90V†
V_{NN} Negative high voltage supply	+0.5V to -90V†
Logic input voltages	-0.5V to V_{DD} +0.3V
Analog signal range	V_{SIG} - V_{NN} = 0 to 144V†
Peak analog signal current/channel	1.5A
Storage temperature	-65°C to +150°C
Power dissipation	800mW

* Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied. Continuous operation of the device at the absolute rating level may affect device reliability.

† For HV1616

Electrical Characteristics

(over recommended operating conditions, V_{PP} = +80V, V_{NN} = -80V and V_{DD} = 15V unless otherwise noted)*

DC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Switch (ON) Resistance	R_{ONS}		50		40	50		60	ohms	I_{SW} = 5mA
Switch (ON) Resistance	R_{ONS}		35		25	35		45	ohms	I_{SW} = 200mA
Switch (ON) Resistance	R_{ONS}		55		45	55		65	ohms	V_{PP} = +50V, V_{NN} = -50V I_{SW} = 5mA
Switch (ON) Resistance	R_{ONS}		40		25	40		50	ohms	V_{PP} = +50V, V_{NN} = -50V I_{SW} = 200mA
Switch (ON) Resistance Matching	ΔR_{ONS}		15			15		15	%	V_{PP} = +50V, V_{NN} = -50V I_{SW} = 5mA
Switch Off Leakage	I_{SOL}		50		0.5	50		150	µA	V_{OUT} = V_{PP} -10V thru 10KΩ with 8 SWS in parallel
DC Offset Switch Off			500		100	500		500	mV	R_L = 100K
DC Offset Switch On			500		100	500		500	mV	R_L = 100K
Pole to Pole Switch Capacitance	C_{SW}		10		4.5	10		10	pF	DC Bias = 40V f = 1MHz
Logic Input Capacitance	C_{IN}				3.5				pF	
Pos. HV Supply Current	I_{PPQ}		200		50	200		200	µA	ALL SWS OFF
Neg. HV Supply Current	I_{NNQ}		-200		-50	-200		-200	µA	
Pos. HV Supply Current	I_{PPQ}				0.8	1.6			mA	1 SW ON
Neg. HV Supply Current	I_{NNQ}				-0.8	-1.6			mA	I_{SW} = 5mA
Pos. HV Supply Current	I_{PPQ}				0.6	1.2			mA	V_{PP} = +50V
Neg. HV Supply Current	I_{NNQ}				-0.6	-1.2			mA	V_{NN} = -50V 1 SW ON, I_{SW} = 5mA
Switch Output Peak Current					1.5				A	V_{SIG} Duty Cycle ≤ 0.1% f = 10KHz
Logic Supply Average Current	I_{DD}				4	6			mA	f_{CLK} = 3MHz
Logic Supply Quiescent Current	I_{DDQ}				10	500			µA	
Data Out Source Current	I_{SOR}	0.7		0.8	0.9		0.7		mA	V_{OUT} = V_{DD} - 0.7V
Data Out Sink Current	I_{SINK}	0.7		0.8	0.9		0.7		mA	V_{OUT} = 0.7V

AC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Set Up Time Before $\overline{LE}$ Rises	t_{SD}			260					ns	
Time Width of $\overline{LE}$	t_{WLE}			300					ns	
Clock Delay Time to Data Out	t_{DO}				250	330			ns	
Turn On Time	t_{ON}		5		2.5	5		5	µs	RL =10KΩ
Turn Off Time	t_{OFF}		10		5.0	10		10	µs	RL =10KΩ
Off Isolation	KO			-35	-45				dB	Signal Freq. = 5MHz
Max Clock Freq	f_{CLK}					3			MHz	50% Duty Cycle f_{DATA} = f_{CLK}/2
Set Up Time Data to Clock	t_{SU}			0					ns	
Hold Time Data from Clock	t_h			35					ns	
Switch Crosstalk	K_{CR}				-45				dB	Signal Freq. = 5MHz

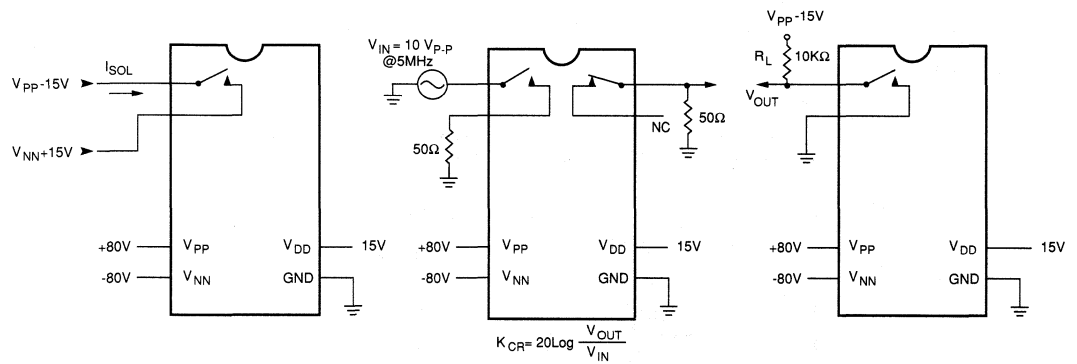
* For HV1616. For HV1614; V_{PP} = +70V. V_{NN} = -70V, and V_{DD} = 15V.

Recommended Operating Conditions

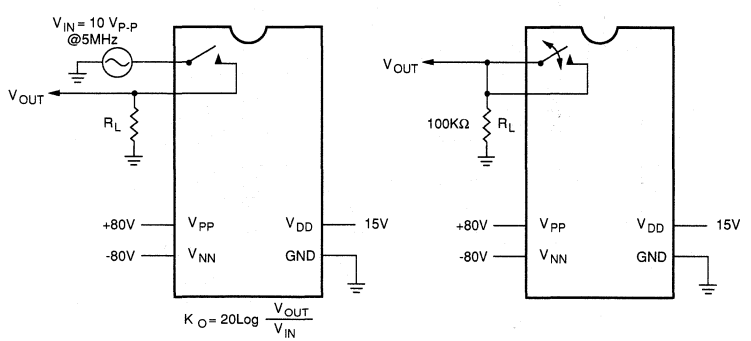
Symbol	Parameter	Device		Value
		HV1614	HV1616	
V_{DD}	Logic power supply voltage	X	X	+10.0V to +15.5V
V_{PP}	Positive high voltage supply	X		+50V to +70V
			X	+50V to +80V
V_{NN}	Negative high voltage supply	X		-50V to -70V
			X	-50V to -80V
V_{IH}	High level input voltage	X	X	V_{DD} -2V to V_{DD}
V_{IL}	Low-level input voltage	X	X	0 to 2.0V
V_{SIG}	Analog signal voltage peak to peak	X	X	V_{NN} +15V to V_{PP} -15V
T_A	Operating free air-temperature	X	X	0° to 70°C

Notes:
1. Power up/down sequence is arbitrary except GND must be powered-up first and powered-down last.
2. V_{SIG} must be $V_{NN} \leq V_{SIG} \leq V_{PP}$ or floating during power up/down transition.

Test Circuits

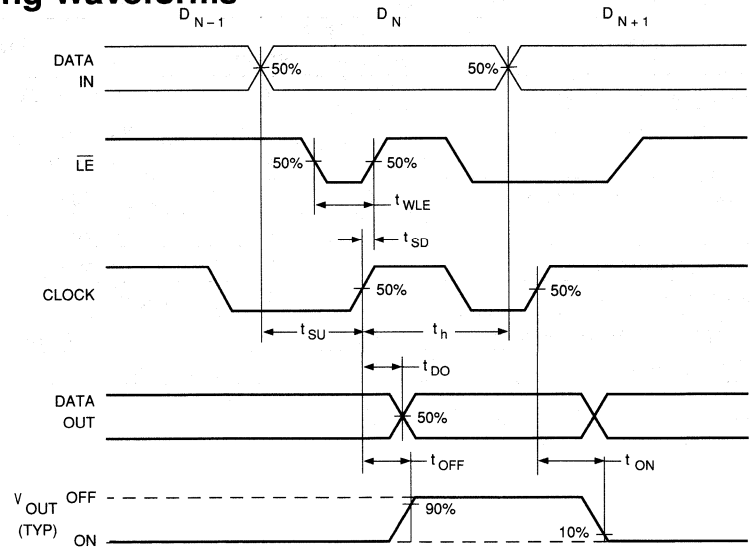


Switch OFF Leakage | Crosstalk | T_{ON} /T_{OFF}

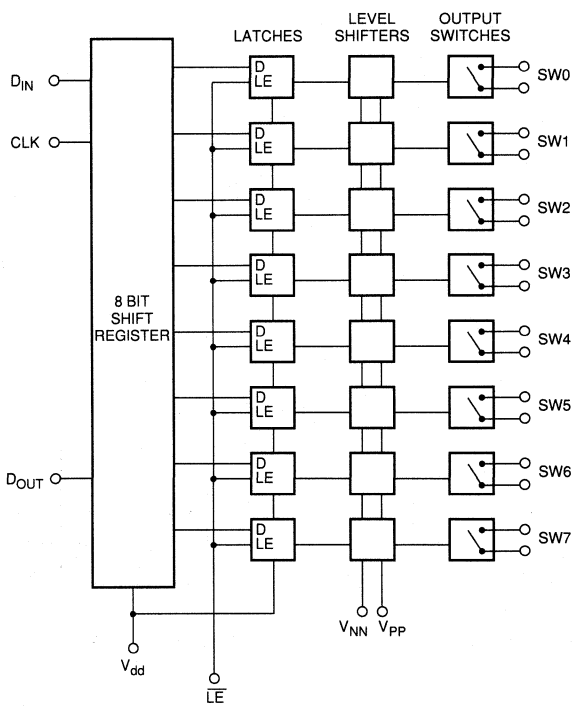


OFF Isolation | DC Offset ON/OFF

Logic Timing Waveforms



Logic Diagram



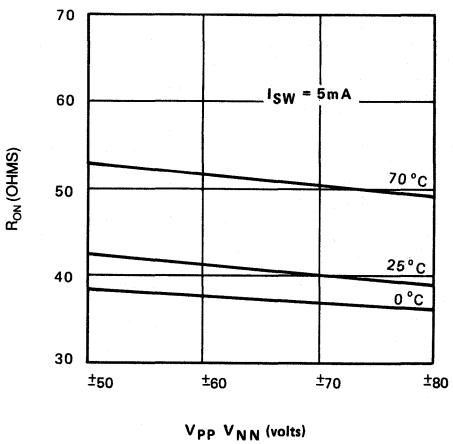
Truth Table

D0	D1	D2	D3	D4	D5	D6	D7	$\overline{LE}$	SW0	SW1	SW2	SW3	SW4	SW5	SW6	SW7
L								L	OFF							
H								L	ON							
	L							L		OFF						
	H							L		ON						
		L						L			OFF					
		H						L			ON					
			L					L				OFF				
			H					L				ON				
				L				L					OFF			
				H				L					ON			
					L			L						OFF		
					H			L						ON		
						L		L							OFF	
						H		L							ON	
							L	L								OFF
							H	L								ON
X	X	X	X	X	X	X	X	H	HOLD PREVIOUS STATE							

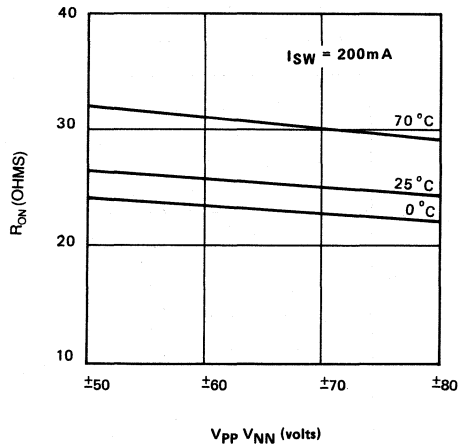
Notes:
1. The eight switches operate independently.
2. Serial data is clocked in on the L → H transition CK.
3. The switches go to a state retaining their present condition at the rising edge of LE. When $\overline{LE}$ is low the shift register data flows through the latch.
4. D_{OUT} is high when switch 7 is on.
5. Shift register clocking has no effect on the switch states if $\overline{LE}$ is H.

Typical Performance Curves

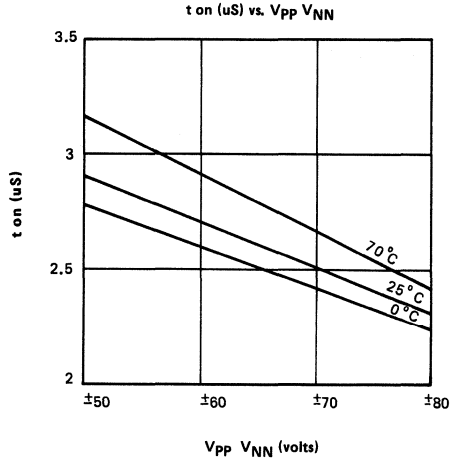
R_{ON} vs. V_{PP} V_{NN}



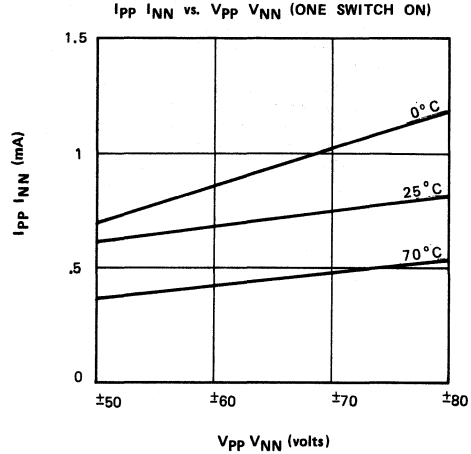
R_{ON} vs. V_{PP} V_{NN}



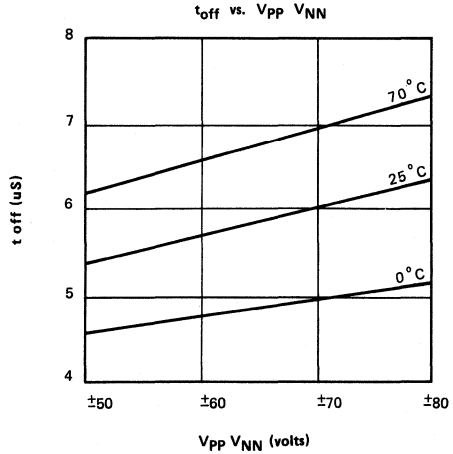
t on (uS) vs. V_{PP} V_{NN}



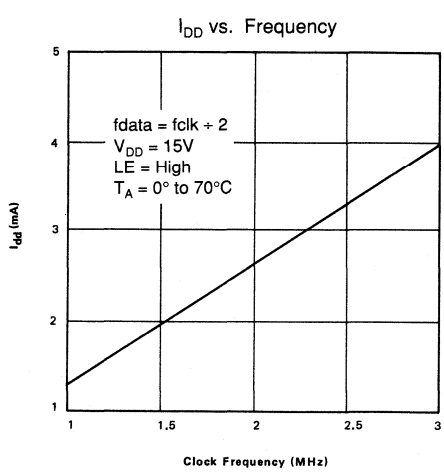
I_{PP} I_{NN} vs. V_{PP} V_{NN} (ONE SWITCH ON)



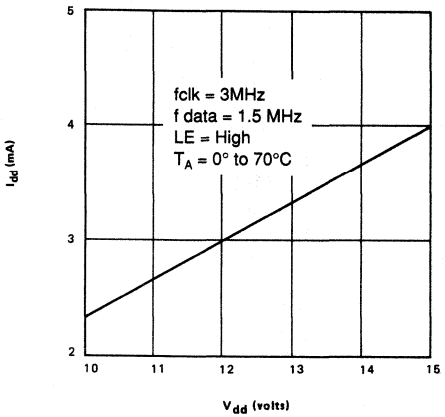
t_{off} vs. V_{PP} V_{NN}



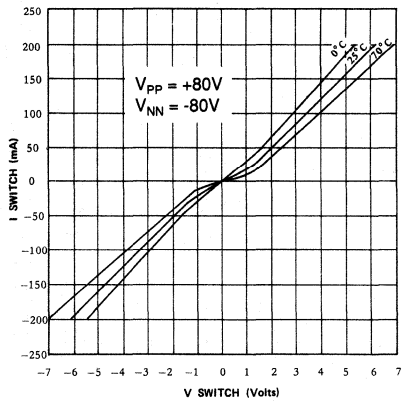
I_{DD} vs. Frequency



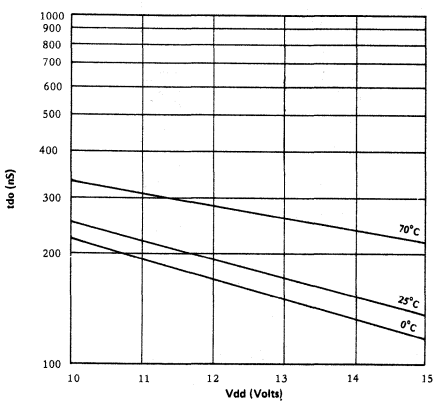
I_{DD} vs. V_{DD}



Switch Current vs. Voltage



T_{DO} vs V_{DD}



Pin Configurations

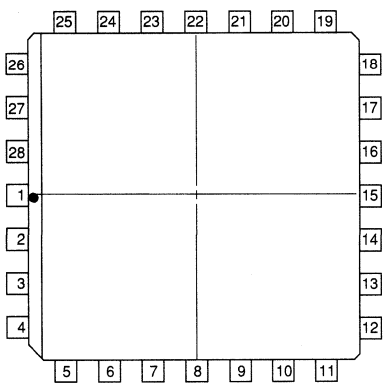
28-Pin J-Lead

Pin	Function	Pin	Function
1	SW3	15	N/C
2	SW3	16	D_{IN}
3	SW2	17	$\overline{CLK}$
4	SW2	18	$\overline{LE}$
5	N/C	19	D_{OUT}
6	N/C	20	SW7
7	SW1	21	SW7
8	SW1	22	SW6
9	SW0	23	SW6
10	SW0	24	N/C
11	V_{PP}	25	SW5
12	V_{NN}	26	SW5
13	GND	27	SW4
14	V_{DD}	28	SW4

24-Pin DIP

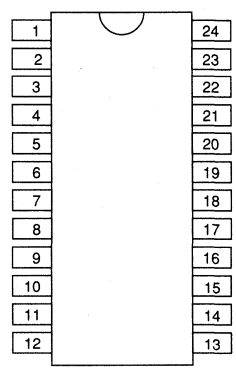
Pin	Function	Pin	Function
1	SW3	13	D_{IN}
2	SW3	14	$\overline{CK}$
3	SW2	15	$\overline{LE}$
4	SW2	16	D_{OUT}
5	SW1	17	SW7
6	SW1	18	SW7
7	SW0	19	SW6
8	SW0	20	SW6
9	V_{PP}	21	SW5
10	V_{NN}	22	SW5
11	GND	23	SW4
12	V_{DD}	24	SW4

Package Outlines



top view

28-pin J-lead Package



top view

24-pin DIP

8-Channel High Voltage Switch

Ordering Information

V_{PP}	V_{NN}	V_{SIG}	Package Options				
			24-pin Ceramic Side-brazed DIP*	Die	36-pin Leaded Ceramic Chip Carrier*	24-pin Plastic DIP	28-lead Plastic Chip Carrier
+70V	-70V	110V P-P	HV1814C	HV1814X	HV1814CS	HV1814P	HV1814PJ
+80V	-80V	130V P-P	HV1816C	HV1816X	HV1816CS	HV1816P	HV1816PJ

* Consult factory for Cerdip and Ceramic LCC availability.

Features

- ☐ HVCMOS® technology
- ☐ Up to 130V peak to peak output switching
- ☐ Output On-resistance typically 40 ohms
- ☐ Low parasitic capacitances
- ☐ DC to 10MHz analog signal frequency
- ☐ 45 dB typical output off isolation at 5 MHz
- ☐ CMOS logic circuitry for low power and excellent noise immunity
- ☐ On-chip shift register, latch with clear function and chip select logic circuitry

General Description

This device is an 8-channel high-voltage integrated circuit (HVIC) intended for use in applications requiring high voltage switching controlled by low voltage signals; e.g., ultrasound imaging and printers. Input data is shifted into an 8-bit shift register which can then be retained in an 8-bit latch. Using HVCMOS technology, this HVIC combines high voltage bi-lateral DMOS switches and low power CMOS logic to provide efficient control of high voltage analog signals.

Absolute Maximum Ratings*

V_{DD} Logic power supply voltage	-0.5V to +18V
V_{PP} - V_{NN} supply voltage	174V†
V_{PP} Positive high voltage supply	-0.5V to +90V†
V_{NN} Negative high voltage supply	+0.5V to -90V†
Logic input voltages	-0.5V to V_{DD} +0.3V
Analog signal range	V_{SIG} - V_{NN} = 0 to 144V†
Peak analog signal current/channel	1.5A
Storage temperature	-65°C to +150°C
Power dissipation	800mW

* Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied. Continuous operation of the device at the absolute rating level may affect device reliability.

† For HV1816

Electrical Characteristics

(over recommended operating conditions, V_{PP} = +80V, V_{NN} = -80V and V_{DD} = 15V unless otherwise noted)*

DC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Switch (ON) Resistance	R_{ONS}		50		40	50		60	ohms	I_{SW} = 5mA
Switch (ON) Resistance	R_{ONS}		35		25	35		45	ohms	I_{SW} = 200mA
Switch (ON) Resistance	R_{ONS}		55		45	55		65	ohms	V_{PP} = +50V, V_{NN} = -50V I_{SW} = 5mA
Switch (ON) Resistance	R_{ONS}		40		25	40		50	ohms	V_{PP} = +50V, V_{NN} = -50V I_{SW} = 200mA
Switch (ON) Resistance Matching	ΔR_{ONS}		15			15		15	%	V_{PP} = +50V, V_{NN} = -50V I_{SW} = 5mA
Switch Off Leakage Per Switch	I_{SOL}		50		0.5	50		150	µA	V_{OUT} = V_{PP} -10V thru 10KΩ with 8 SWS in parallel
DC Offset Switch Off			500		100	500		500	mV	R_L = 100K
DC Offset Switch On			500		100	500		500	mV	R_L = 100K
Pole to Pole Switch Capacitance	C_{SW}		10		4.5	10		10	pF	DC Bias = 40V f = 1MHz
Logic Input Capacitance	C_{IN}				3.5				pF	
Pos. HV Supply Current	I_{PPQ}		200		50	200		200	µA	ALL SWS OFF
Neg. HV Supply Current	I_{NNQ}		-200		-50	-200		-200	µA	
Pos. HV Supply Current	I_{PPQ}				0.8	1.6			mA	1 SW ON
Neg. HV Supply Current	I_{NNQ}				-0.8	-1.6			mA	I_{SW} = 5mA
Pos. HV Supply Current	I_{PPQ}				0.6	1.2			mA	V_{PP} = +50V
Neg. HV Supply Current	I_{NNQ}				-0.6	-1.2			mA	V_{NN} = -50V 1 SW ON, I_{SW} = 5mA
Switch Output Peak Current					1.5				A	V_{SIG} Duty Cycle ≤ 0.1% f = 10KHz
Logic Supply Average Current	I_{DD}				4	6			mA	f_{CLK} = 3MHz
Logic Supply Quiescent Current	I_{DDQ}				10	500			µA	
Data Out Source Current	I_{SOR}	0.7		0.8	0.9		0.7		mA	V_{OUT} = V_{DD} - 0.7V
Data Out Sink Current	I_{SINK}	0.7		0.8	0.9		0.7		mA	V_{OUT} = 0.7V

AC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Set Up Time Before $\overline{LE}$ Rises	t_{SD}			260					ns	
Time Width of $\overline{LE}$	t_{WLE}			300					ns	
Clock Delay Time to Data Out	t_{DO}				250	330			ns	
Turn On Time	t_{ON}		5		2.5	5		5	µs	R_L =10KΩ
Turn Off Time	t_{OFF}		10		5.0	10		10	µs	R_L =10KΩ
Time Width of CL	t_{WCL}			5					µs	
Off Isolation	KO			-35	-45				dB	Signal Freq. = 5MHz
Max Clock Freq	f_{CLK}					3			MHz	50% Duty Cycle f_{DATA} = f_{CLK}/2
Set Up Time Data to Clock	t_{SU}			0					ns	
Hold Time Data from Clock	t_h			35					ns	
Switch Crosstalk	K_{CR}				-45				dB	Signal Freq. = 5MHz

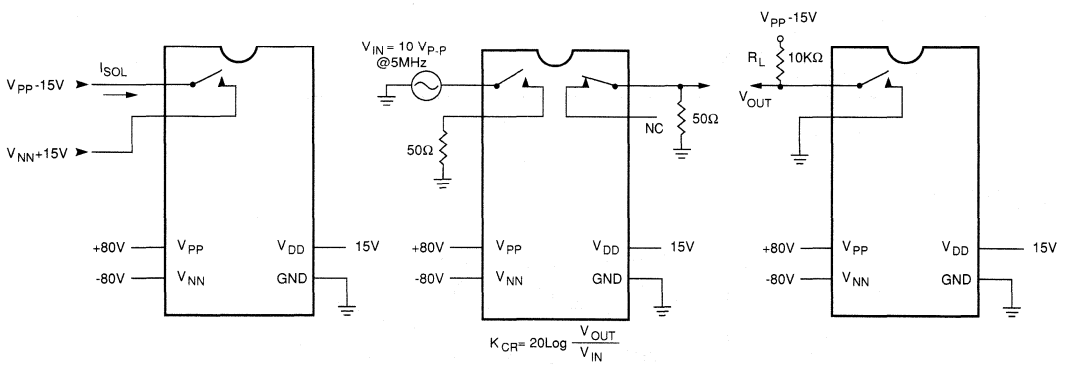
*For HV1816.For HV1814; V_{PP} = +70V. V_{NN} = -70V, and V_{DD} = 15V unless otherwise noted)

Recommended Operating Conditions

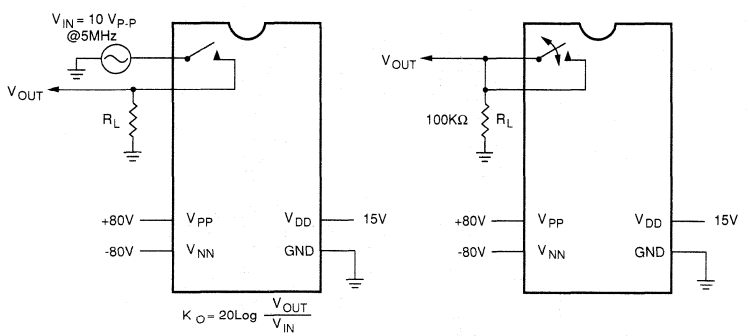
Symbol	Parameter	Device		Value
		HV1814	HV1816	
V_{DD}	Logic power supply voltage	X	X	+10.0V to +15.5V
V_{PP}	Positive high voltage supply	X		+50V to +70V
			X	+50V to +80V
V_{NN}	Negative high voltage supply	X		-50V to -70V
			X	-50V to -80V
V_{IH}	High level input voltage	X	X	V_{DD} -2V to V_{DD}
V_{IL}	Low-level input voltage	X	X	0 to 2.0V
V_{SIG}	Analog signal voltage peak to peak	X	X	V_{NN} +15V to V_{PP} -15V
T_A	Operating free air-temperature	X	X	0° to 70°C

Notes:
1. Power up/down sequence is arbitrary except GND must be powered-up first and powered-down last.
2. V_{SIG} must be $V_{NN} \leq V_{SIG} \leq V_{PP}$ or floating during power up/down transition.

Test Circuits

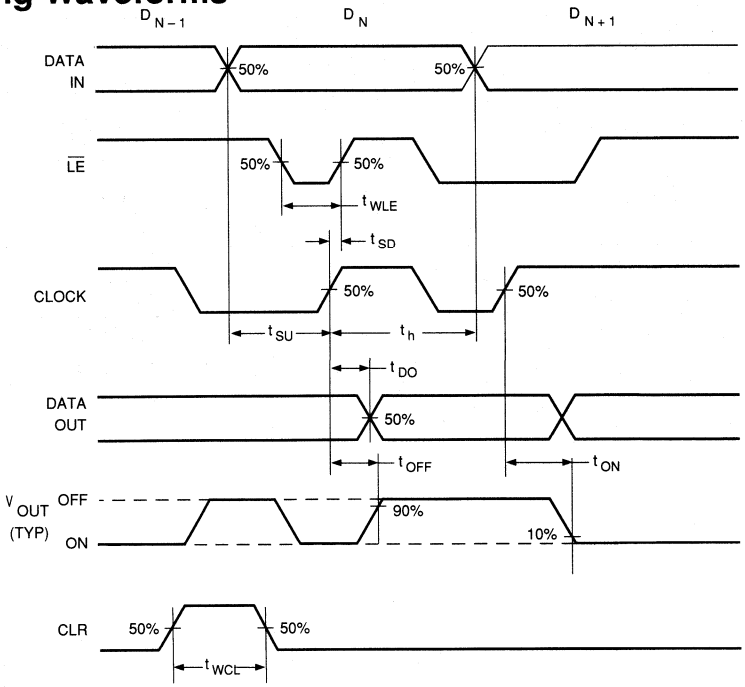


Switch OFF Leakage | Crosstalk | T_{ON} /T_{OFF}

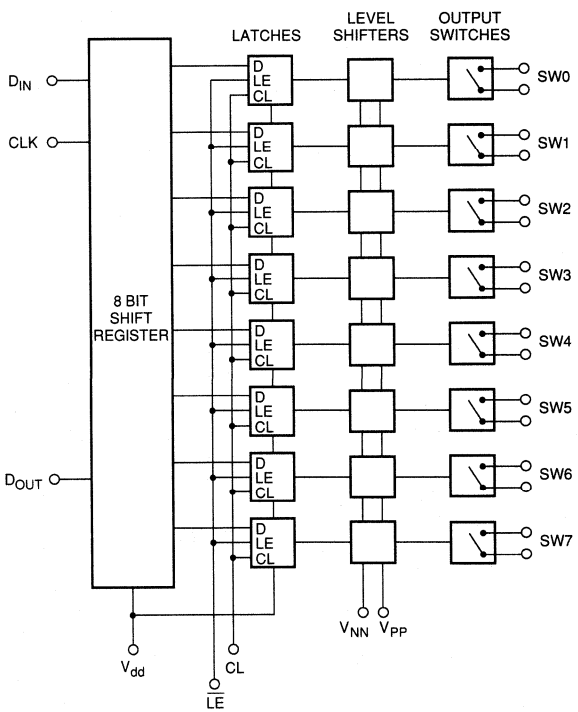


OFF Isolation | DC Offset ON/OFF

Logic Timing Waveforms



Logic Diagram

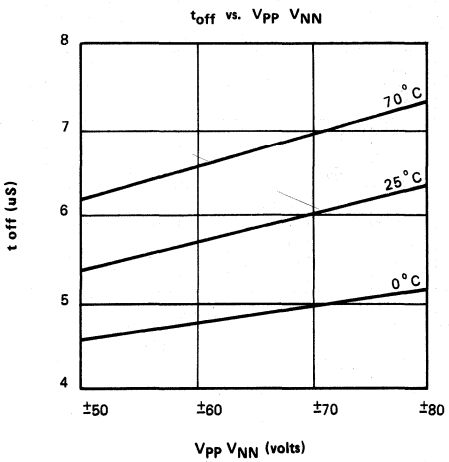


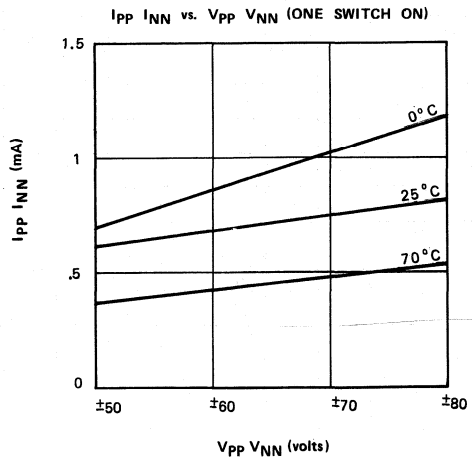
Truth Table

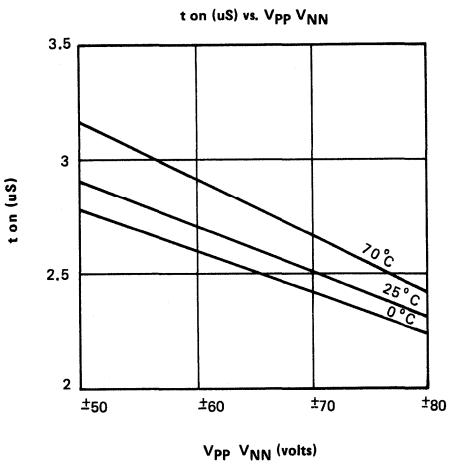
D_0	D_1	D_2	D_3	D_4	D_5	D_6	D_7	$\overline{LE}$	CL	SW_0	SW_1	SW_2	SW_3	SW_4	SW_5	SW_6	SW_7
L								L	L	OFF							
H								L	L	ON							
	L							L	L		OFF						
	H							L	L		ON						
		L						L	L			OFF					
		H						L	L			ON					
			L					L	L				OFF				
			H					L	L				ON				
				L				L	L					OFF			
				H				L	L					ON			
					L			L	L						OFF		
					H			L	L						ON		
						L		L	L							OFF	
						H		L	L							ON	
							L	L	L								OFF
							H	L	L								ON
X	X	X	X	X	X	X	X	X	H	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF
X	X	X	X	X	X	X	X	H	L	HOLD PREVIOUS STATE							

Notes:
1. The eight switches operate independently.
2. Serial data is clocked in on the L → H transition CK.
3. The clear input over rides all other inputs.
4. The switches go to a state retaining their present condition at the rising edge of $\overline{LE}$. When $\overline{LE}$ is low the shift register data flows through the latch.
5. D_{OUT} is high when switch 7 is on.
6. Shift register clocking has no effect on the switch states if $\overline{LE}$ is H.

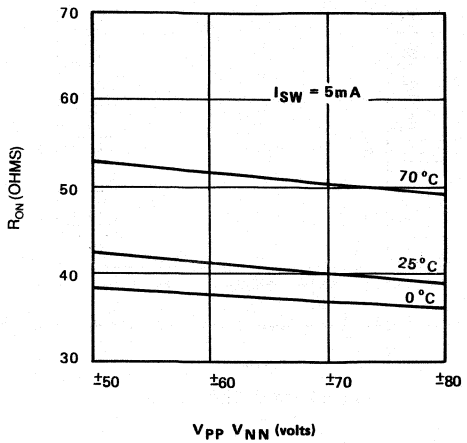
Typical Performance Curves



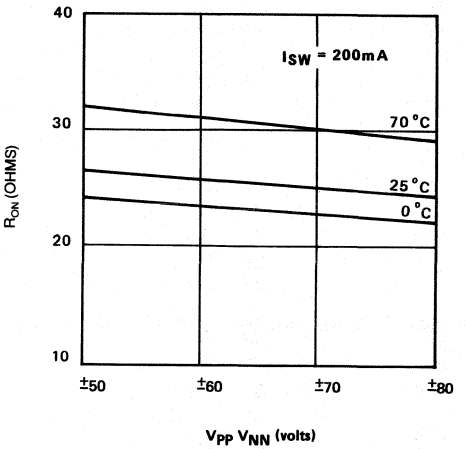




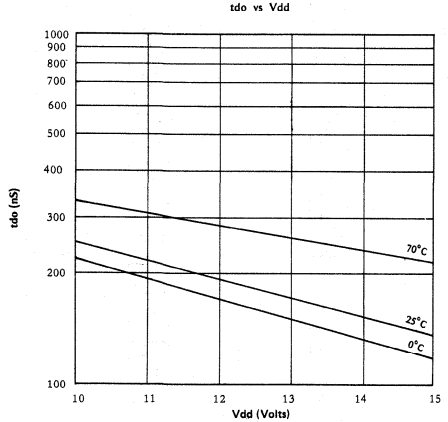
R_{ON} vs. V_{PP} V_{NN}



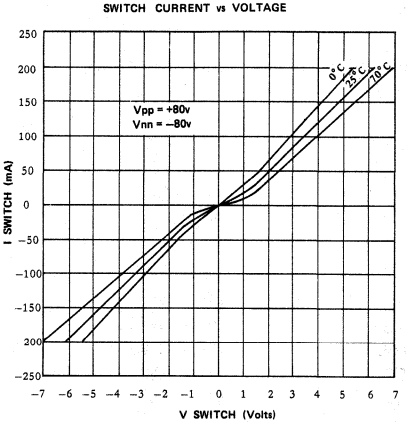
R_{ON} vs. V_{PP} V_{NN}



tdo vs Vdd



SWITCH CURRENT vs VOLTAGE



Pin Configurations

36-Pin Leaded Chip Carrier

Pin	Function	Pin	Function
1	SW3	19	N/C
2	SW3	20	D_{IN}
3	N/C	21	$\overline{CK}$
4	SW2	22	$\overline{LE}$
5	SW2	23	CL
6	N/C	24	D_{OUT}
7	SW1	25	SW7
8	SW1	26	SW7
9	N/C	27	N/C
10	SW0	28	SW6
11	SW0	29	SW6
12	N/C	30	N/C
13	N/C	31	SW5
14	V_{PP}	32	SW5
15	V_{NN}	33	N/C
16	GND	34	SW4
17	V_{DD}	35	SW4
18	N/C	36	N/C

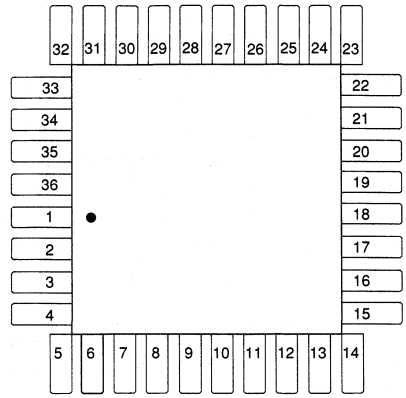
28-Pin DIP

Pin	Function	Pin	Function
1	SW3	15	N/C
2	SW3	16	D_{IN}
3	SW2	17	$\overline{CK}$
4	SW2	18	$\overline{LE}$
5	SW1	19	CL
6	SW1	20	D_{OUT}
7	SW0	21	SW7
8	SW0	22	SW7
9	V_{PP}	23	SW6
10	V_{NN}	24	SW6
11	N/C	25	SW5
12	GND	26	SW5
13	V_{DD}	27	SW4
14	N/C	28	SW4

28-Pin J-Lead

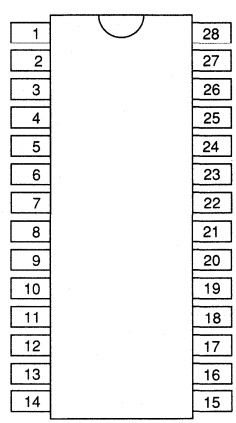
Pin	Function	Pin	Function
1	SW3	15	N/C
2	SW3	16	D_{IN}
3	SW2	17	$\overline{CK}$
4	SW2	18	$\overline{LE}$
5	SW1	19	CL
6	SW1	20	D_{OUT}
7	SW0	21	SW7
8	SW0	22	SW7
9	V_{PP}	23	SW6
10	V_{NN}	24	SW6
11	N/C	25	SW5
12	GND	26	SW5
13	V_{DD}	27	SW4
14	N/C	28	SW4

Package Outlines



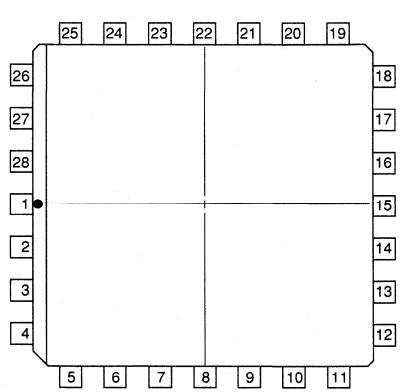
top view

36-pin Leaded Chip Carrier



top view

28-pin DIP



top view

28-pin J-lead Package

8-Channel High Voltage Analog Switch

Ordering Information

$V_{PP} - V_{NN}$	Package Options			
	24-pin ceramic*† side-brazed DIP	Die in waffle pack	24-pin plastic DIP	28-lead plastic chip carrier
140V	HV2114C	HV2114X	HV2114P	HV2114PJ
160V	HV2116C	HV2116X	HV2116P	HV2116PJ

* Consult factory for Cerdip and Ceramic LCC availability.
† Consult factory for MIL-STD-883 processing. See page 5-3 for process flow.

Features

- ☐ HVCMOS® Technology for high performance
- ☐ Very low quiescent power dissipation – 10μA
- ☐ Output On-resistance typically 22 ohms
- ☐ Low parasitic capacitances
- ☐ DC to 10MHz analog signal frequency
- ☐ 50dB typical output off isolation at 5 MHz
- ☐ CMOS logic circuitry for low power
- ☐ Excellent noise immunity
- ☐ On-chip shift register, latch and chip select logic circuitry
- ☐ Flexible high voltage supplies
- ☐ Surface mount package available

General Description

This device is an 8-channel high-voltage analog switch integrated circuit (IC) intended for use in applications requiring high voltage switching controlled by low voltage control signals, such as ultrasound imaging and printers. Input data is shifted into an 8-bit shift register which can then be retained in an 8-bit latch. To reduce any possible clock feedthrough noise, Latch Enable Bar ($\overline{LE}$) should be left high until all bits are clocked in. Using HVCMOS technology, this switch combines high voltage bi-lateral DMOS switches and low power CMOS logic to provide efficient control of high voltage analog signals.

This IC is suitable for various combinations of high voltage supplies, e.g. for HV2116 +40V/-120V, or +80V/-80V or +150V/-10V.

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Absolute Maximum Ratings*

V_{DD} logic power supply voltage	-0.5V to +18V
V_{PP} - V_{NN} supply voltage	174V†
V_{PP} positive high voltage supply	-0.5V to V_{NN} +160V†
V_{NN} Negative high voltage supply	+0.5V to -130V†
Logic input voltages	-0.5V to V_{DD} +0.3V
Analog signal range	V_{SIG} - V_{NN} = 0 to 154V†
Peak analog signal current/channel	3.0A
Storage temperature	-65°C to +150°C
Power dissipation	Plastic Package 0.8W
	Ceramic Package 2.0W

* Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied. Continuous operation of the device at the absolute rating level may affect device reliability.
† For HV2116

Electrical Characteristics

(over recommended operating conditions, V_{PP} = +80V, V_{NN} = -80V, and V_{DD}= 15V unless otherwise noted)*

DC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Small Signal Switch (ON) Resistance	R_{ONS}		25		22	27		30	ohms	I_{SIG} = 5mA
	R_{ONS}		18		18	20		23	ohms	I_{SIG} = 200mA
Small Signal Switch (ON) Resistance Matching	ΔR_{ONS}		20		5	20		20	%	I_{SW} = 5mA
Large Signal Switch (ON) Resistance	R_{ONL}		90		70	100		120	ohms	$V_{SIG} = V_{PP}$ -10V, I_{SIG} = 5mA
Switch Off Leakage Per Switch	I_{SOL}		5		1	10		15	µA	$V_{SIG} = V_{PP}$ -10V and V_{NN} +10V
DC Offset Switch Off			300		100	300		300	mV	R_L = 100K
DC Offset Switch On			500		100	500		500	mV	R_L = 100K
Pos. HV Supply Current	I_{PPQ}				10	50			µA	ALL SWS OFF
Neg. HV Supply Current	I_{NNQ}				-10	-50			µA	
Pos. HV Supply Current	I_{PPQ}				10	50			µA	ALL SWS ON I_{SW} = 5mA
Neg. HV Supply Current	I_{NNQ}				-10	-50			µA	
Switch Output Peak Current			3.0		3.0	2.0		2.0	A	V_{SIG} duty cycle ≤ 0.1%
Output Switch Frequency	f_{SW}					50			KHz	Duty Cycle = 50%
I_{PP} Supply Current	I_{PP}		4.0		3.5	5.0		5.5	mA	HV output switching frequency = 50KHz
I_{NN} Supply Current	I_{NN}		4.0		3.5	5.0		5.5	mA	
Logic Supply Average Current	I_{DD}		6		4	6		6	mA	f_{CLK} = 3MHz
Logic Supply Quiescent Current	I_{DDQ}		10			10		10	µA	
Data Out Source Current	I_{SOR}	0.45		0.45	0.70		0.40		mA	$V_{OUT} = V_{DD}$ - 0.7V
Data Out Sink Current	I_{SINK}	0.45		0.45	0.70		0.40		mA	V_{OUT} = 0.7V

AC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Set Up Time Before $\overline{LE}$ Rises	t_{SD}	150		150			150		ns	
Time Width of $\overline{LE}$	t_{WLE}	150		150			150		ns	
Clock Delay Time to Data Out	t_{DO}		300		150	330		350	ns	
Turn On Time	t_{ON}		2		0.2	2		2	µs	R_L = 10KΩ
Turn Off Time	t_{OFF}		3		0.5	3		3	µs	R_L = 10KΩ
Off Isolation	KO	-30		-30	-33		-30		dB	f = 5MHz, 1KΩ// 15pF load
		-45		-45	-50		-45		dB	f = 5MHz, 50Ω load
Clock Freq	f_{CLK}					3			MHz	50% duty cycle $f_{DATA} = f_{CLK}/2$
Set Up Time Data to Clock	t_{SU}	15		15	8		20		ns	
Hold Time Data from Clock	t_h			35					ns	
Switch Crosstalk	K_{CR}	-60		-60	-70		-60		dB	f = 5MHz, 50Ω load
Off Capacitance SW to GND	$C_{SG(OFF)}$		11		9	11		11	pF	0V, 1MHz
On Capacitance SW to GND	$C_{SG(ON)}$		40		34	40		40	pF	0V, 1MHz

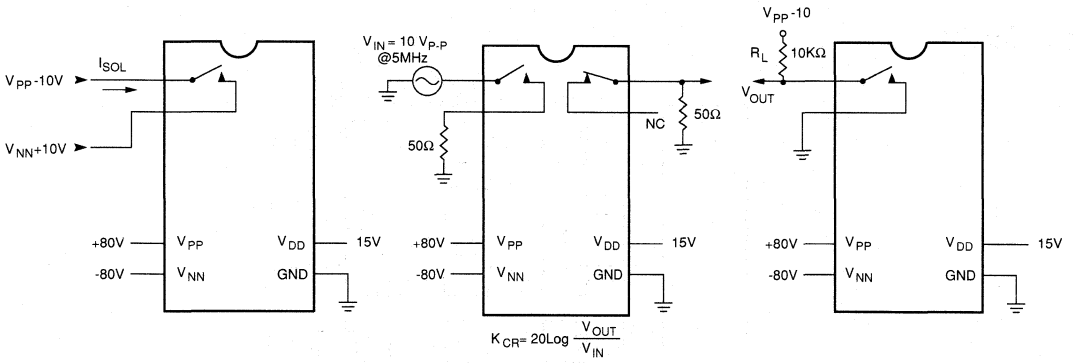
* For HV2116. For HV2114: V_{PP} = 70V, V_{NN} = -70V and V_{DD} = 15V

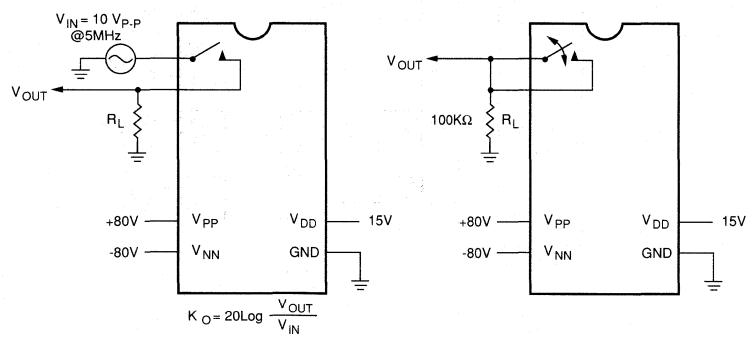
Recommended Operating Conditions

Symbol	Parameter	Device		Value
		HV2114	HV2116	
V_{DD}	Logic power supply voltage	X	X	10.0 V to 15.5 V
V_{PP}	Positive high voltage supply*	X		40V to V_{NN}+ 140V
			X	40V to V_{NN}+ 160V
V_{NN}	Negative high voltage supply	X		-10.0V to -100V
			X	-10.0V to -120V
V_{IH}	High level input voltage	X	X	V_{DD} -2V to V_{DD}
V_{IL}	Low-level input voltage	X	X	0V to 2.0V
V_{SIG}	Analog signal voltage peak to peak	X	X	V_{NN} +10V to V_{PP} -10
T_A	Operating free air-temperature	X	X	0°C to 70°C

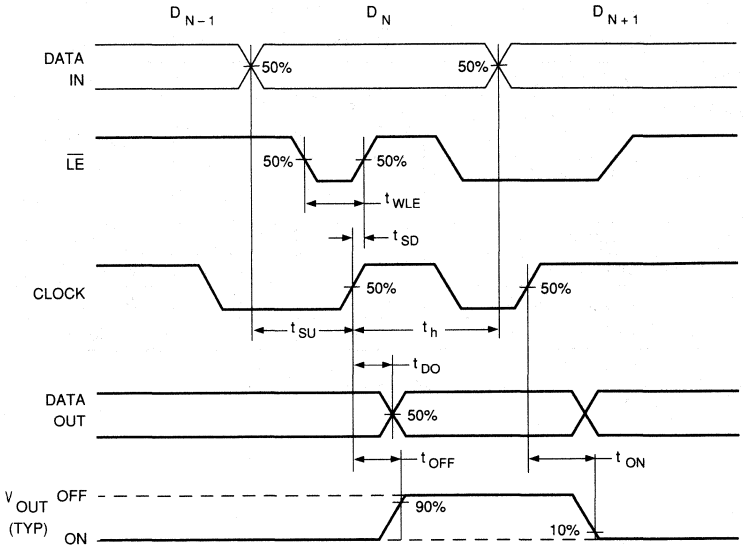
Note:
Power up/down sequence is arbitrary except GND must be powered-down first and powered-down last.
* V_{SIG} must be $V_{NN} \leq V_{SIG} \leq V_{PP}$ or floating during power up/down transistion.

Test Circuits

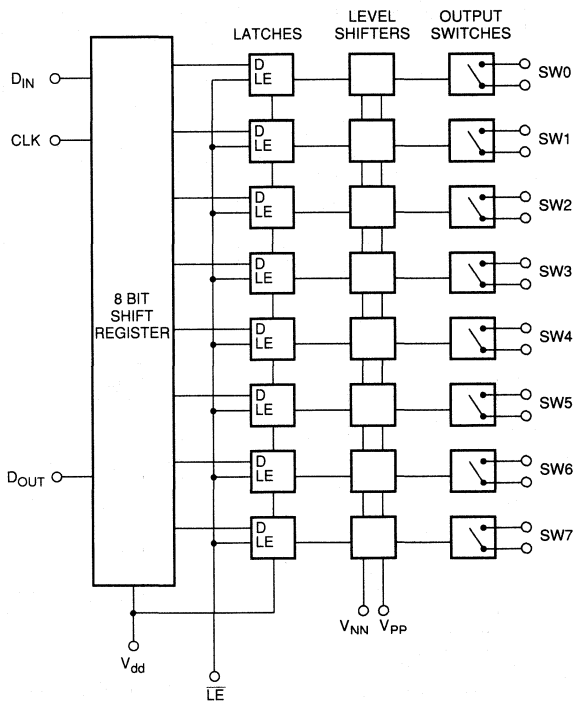




Logic Timing Waveforms



Logic Diagram



Truth Table

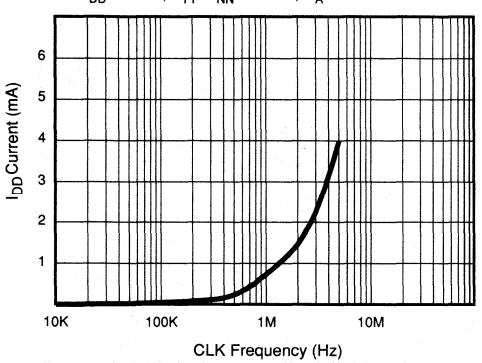
D0	D1	D2	D3	D4	D5	D6	D7	$\overline{LE}$	SW0	SW1	SW2	SW3	SW4	SW5	SW6	SW7
L								L	OFF							
H								L	ON							
	L							L		OFF						
	H							L		ON						
		L						L			OFF					
		H						L			ON					
			L					L				OFF				
			H					L				ON				
				L				L					OFF			
				H				L					ON			
					L			L						OFF		
					H			L						ON		
						L		L							OFF	
						H		L							ON	
							L	L								OFF
							H	L								ON
X	X	X	X	X	X	X	X	H	HOLD PREVIOUS STATE							

Notes:
1. The eight switches operate independently.
2. Serial data is clocked in on the L→ H transition CK.
3. The switches go to a state retaining their present condition at the rising edge of $\overline{LE}$. When $\overline{LE}$ is low the shift register data flows through the latch.
4. D_{OUT} is high when switch 7 is on.
5. Shift register clockng has no effect on the switch states if $\overline{LE}$ is H.

Typical Performance Curves

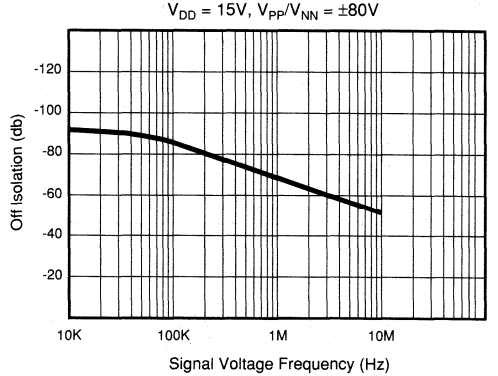
I_{DD} vs CLK Frequency

V_{DD} = 15 V, V_{PP}/V_{NN} = ±80V, T_A = 0°C to 70°C



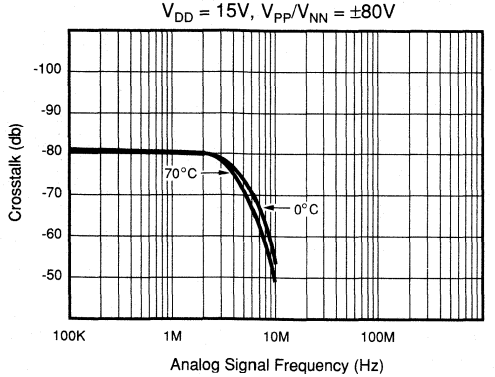
Off Isolation vs Signal Voltage Frequency

V_{DD} = 15V, V_{PP}/V_{NN} = ±80V



Crosstalk vs Analog Signal Frequency

V_{DD} = 15V, V_{PP}/V_{NN} = ±80V



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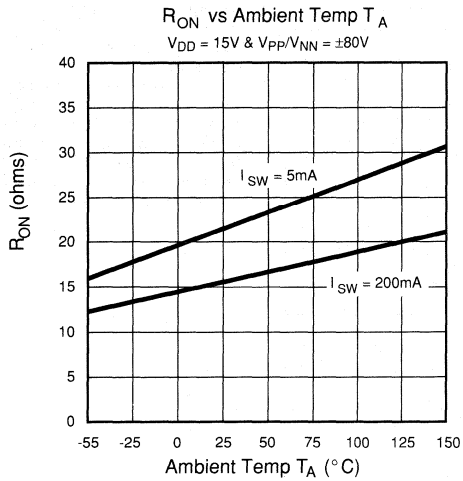
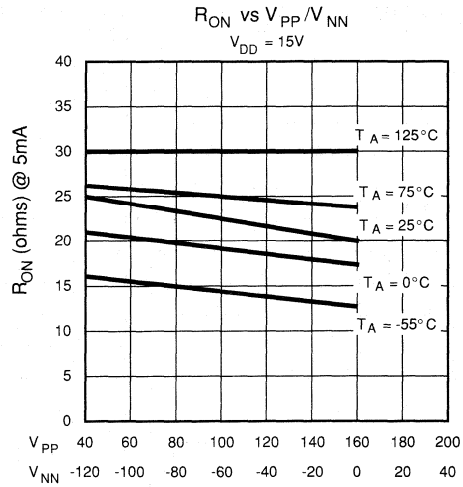
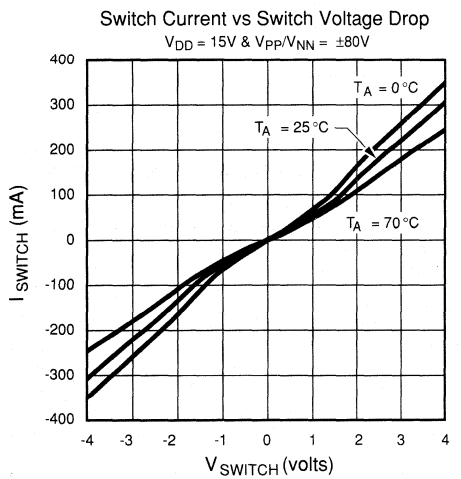
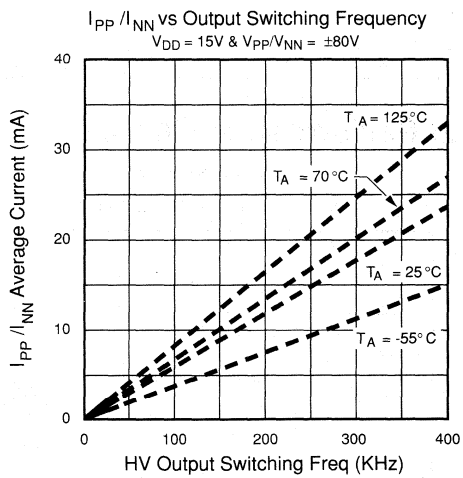
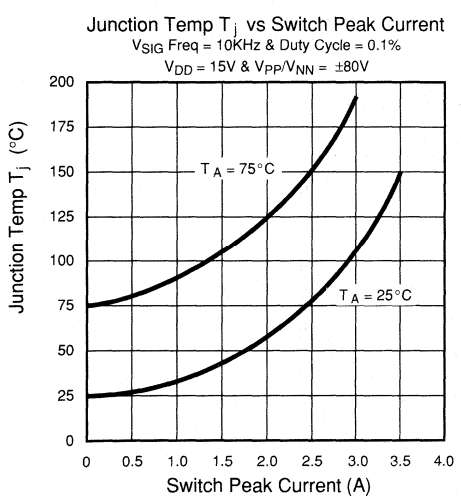
Typical Performance Curves

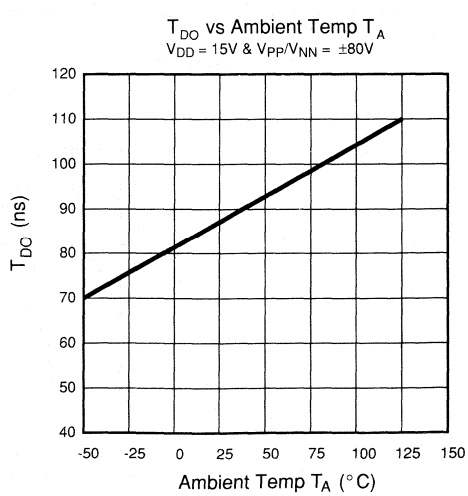










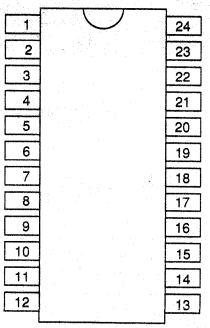


Pin Configurations

24-Pin DIP

Pin	Function	Pin	Function
1	SW3	13	D_{IN}
2	SW3	14	CLK
3	SW2	15	$\overline{LE}$
4	SW2	16	D_{OUT}
5	SW1	17	SW7
6	SW1	18	SW7
7	SW0	19	SW6
8	SW0	20	SW6
9	V_{PP}	21	SW5
10	V_{NN}	22	SW5
11	GND	23	SW4
12	V_{DD}	24	SW4

Package Outlines

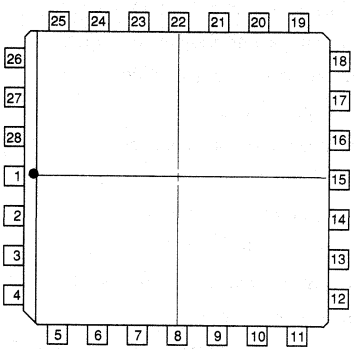


top view

24-pin DIP

28-Pin J-Lead

Pin	Function	Pin	Function
1	SW3	15	N/C
2	SW3	16	D_{IN}
3	SW2	17	CLK
4	SW2	18	$\overline{LE}$
5	N/C	19	D_{OUT}
6	N/C	20	SW7
7	SW1	21	SW7
8	SW1	22	SW6
9	SW0	23	SW6
10	SW0	24	N/C
11	V_{PP}	25	SW5
12	V_{NN}	26	SW5
13	GND	27	SW4
14	V_{DD}	28	SW4



top view

28-pin J-lead Package

8-Channel High Voltage Analog Switch

Ordering Information

$V_{PP} - V_{NN}$	Package Options			
	28-pin ceramic*† side-brazed DIP	Die in waffle pack	28-pin plastic DIP	28-lead plastic chip carrier
140V	HV2214C	HV2214X	HV2214P	HV2214PJ
160V	HV2216C	HV2216X	HV2216P	HV2216PJ

* Consult factory for Cerdip and Ceramic LCC availability.
† Consult factory for MIL-STD-883 processing. See page 5-3 for process flow.

Features

- ☐ HVCMOS® Technology for high performance
- ☐ Very low quiescent power dissipation – 10μA
- ☐ Output On-resistance typically 22 ohms
- ☐ Low parasitic capacitances
- ☐ DC to 10MHz analog signal frequency
- ☐ 50dB typical output off isolation at 5 MHz
- ☐ CMOS logic circuitry for low power
- ☐ Excellent noise immunity
- ☐ On-chip shift register, latch and chip select logic circuitry
- ☐ Flexible high voltage supplies
- ☐ Surface mount package available

General Description

This device is an 8-channel high-voltage analog switch integrated circuit (IC) intended for use in applications requiring high voltage switching controlled by low voltage control signals, such as ultrasound imaging and printers. Input data is shifted into an 8-bit shift register which can then be retained in an 8-bit latch. To reduce any possible clock feedthrough noise, Latch Enable Bar ($\overline{LE}$) should be left high until all bits are clocked in. Using HVCMOS technology, this switch combines high voltage bi-lateral DMOS switches and low power CMOS logic to provide efficient control of high voltage analog signals.

This IC is suitable for various combinations of high voltage supplies, e.g. for HV2216 +40V/-120V, or +80V/-80V or +150V/-10V.

Absolute Maximum Ratings*

V_{DD} Logic power supply voltage	-0.5V to +18V
V_{PP} - V_{NN} Supply voltage	174V†
V_{PP} Positive high voltage supply	-0.5V to V_{NN} +160V†
V_{NN} Negative high voltage supply	+0.5V to -130V†
Logic input voltages	-0.5V to V_{DD} +0.3V
Analog Signal Range	V_{SIG} - V_{NN} = 0V to 154V
Peak analog signal current/channel	3.0A
Storage temperature	-65°C to +150°C
Power dissipation	Plastic Package 0.8W Ceramic Package 2.0W

* Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied. Continuous operation of the device at the absolute rating level may affect device reliability.
† For HV2216

Electrical Characteristics

(over recommended operating conditions, V_{PP} = +80V, V_{NN} = -80V, and V_{DD}= 15V unless otherwise noted)*

DC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Small Signal Switch (ON)	R_{ONS}		25		22	27		30	ohms	I_{SIG} = 5mA
Resistance	R_{ONS}		18		18	20		23	ohms	I_{SIG} = 200mA
Small Signal Switch (ON) Resistance Matching	ΔR_{ONS}		20		5	20		20	%	I_{SW} = 5mA
Large Signal Switch (ON) Resistance	R_{ONL}		90		70	100		120	ohms	$V_{SIG} = V_{PP}$ -10V, I_{SIG} = 5mA
Switch Off Leakage Per Switch	I_{SOL}		5		1	10		15	µA	$V_{SIG} = V_{PP}$ -10V and V_{NN} +10V
DC Offset Switch Off			300		100	300		300	mV	R_L = 100K
DC Offset Switch On			500		100	500		500	mV	R_L = 100K
Pos. HV Supply Current	I_{PPQ}				10	50			µA	ALL SWS OFF
Neg. HV Supply Current	I_{NNQ}				-10	-50			µA	
Pos. HV Supply Current	I_{PPQ}				10	50			µA	ALL SWS ON I_{SW} = 5mA
Neg. HV Supply Current	I_{NNQ}				-10	-50			µA	
Switch Output Peak Current			3.0		3.0	2.0		2.0	A	V_{SIG} duty cycle ≤ 0.1%
Output Switch Frequency		f_{SW}				50			KHz	Duty Cycle = 50%
I_{PP} Supply Current	I_{PP}		4.0		3.5	5.0		5.5	mA	HV output switching frequency = 50KHz
I_{NN} Supply Current	I_{NN}		4.0		3.5	5.0		5.5	mA	
Logic Supply Average Current	I_{DD}		6		4	6		6	mA	f_{CLK} = 3MHz,
Logic Supply Quiescent Current	I_{DDQ}		10			10		10	µA	
Data Out Source Current	I_{SOR}	0.45		0.45	0.70		0.40		mA	$V_{OUT} = V_{DD}$ - 0.7V
Data Out Sink Current	I_{SINK}	0.45		0.45	0.70		0.40		mA	V_{OUT} = 0.7V

AC Characteristics

Characteristics	Sym	0°C		+25°C			+70°C		Units	Test Conditions
		min	max	min	typ	max	min	max		
Set Up Time Before $\overline{LE}$ Rises	t_{SD}	150		150			150		ns	
Time Width of $\overline{LE}$	t_{WLE}	150		150			150		ns	
Clock Delay Time to Data Out	t_{DO}		300		150	330		350	ns	
Turn On Time	t_{ON}		2		0.2	2		2	µs	R_L = 10KΩ
Turn Off Time	t_{OFF}		3		0.5	3		3	µs	R_L = 10KΩ
Time Width of CL	t_{WCL}			5					µs	
Off Isolation	KO	-30		-30	-33		-30		dB	f = 5MHz, 1KΩ// 15pF load
		-45		-45	-50		-45		dB	f = 5MHz, 50Ω load
Clock Freq	f_{CLK}					3			MHz	50% duty cycle $f_{DATA} = f_{CLK}/2$
Set Up Time Data to Clock	t_{SU}	15		15	8		20		ns	
Hold Time Data from Clock	t_h			35					ns	
Switch Crosstalk	K_{CR}	-60		-60	-70		-60		dB	f = 5MHz, 50Ω load
Off Capacitance SW to GND	$C_{SG(OFF)}$		11		9	11		11	pF	0V, 1MHz
On Capacitance SW to GND	$C_{SG(ON)}$		40		34	40		40	pF	0V, 1MHz

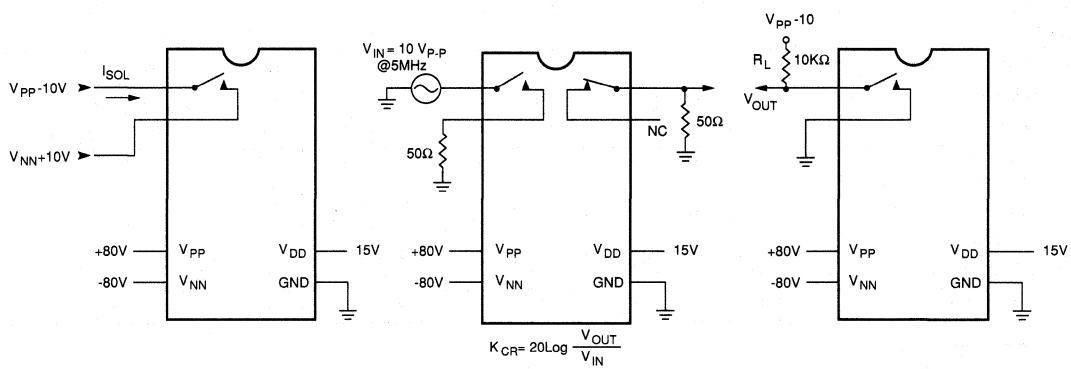
* For HV2216. For HV2214: V_{PP} = 70V, V_{NN} = -70V and V_{DD} = 15V

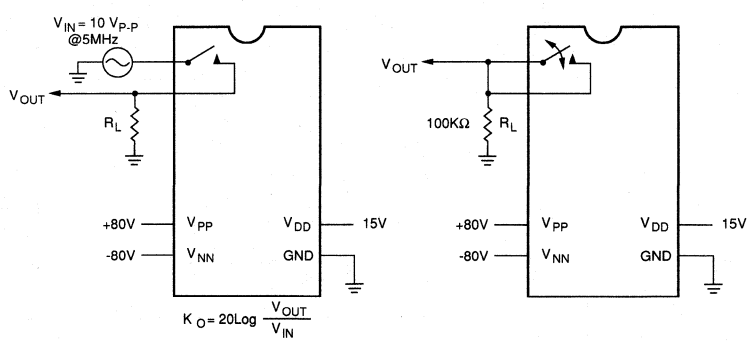
Recommended Operating Conditions

Symbol	Parameter	Device		Value
		HV2214	HV2216	
V_{DD}	Logic power supply voltage	X	X	10.0 V to 15.5 V
V_{PP}	Positive high voltage supply	X		40V to V_{NN}+ 140V
			X	40V to V_{NN}+ 160V
V_{NN}	Negative high voltage supply	X		-10.0V to -100V
			X	-10.0V to -120V
V_{IH}	High level input voltage	X	X	V_{DD} -2V to V_{DD}
V_{IL}	Low-level input voltage	X	X	0V to 2.0V
V_{SIG}*	Analog signal voltage peak to peak	X	X	V_{NN} +10V to V_{PP} -10
T_A	Operating free air-temperature	X	X	0°C to 70°C

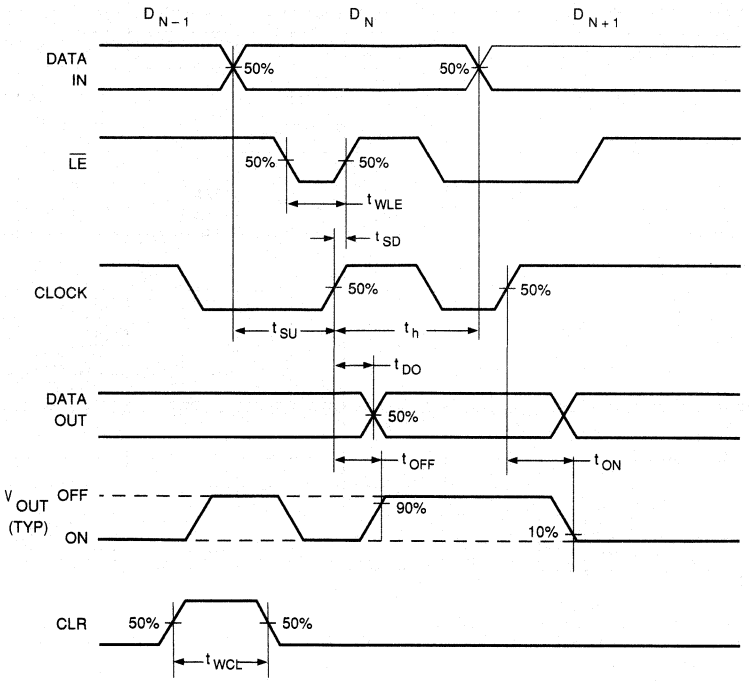
Note:
Power up/down sequence is arbitrary except GND must be powered-up first and powered-down last.
* V_{SIG} must be $V_{NN} \leq V_{SIG} \leq V_{PP}$ or floating during power up/down transistion.

Test Circuits

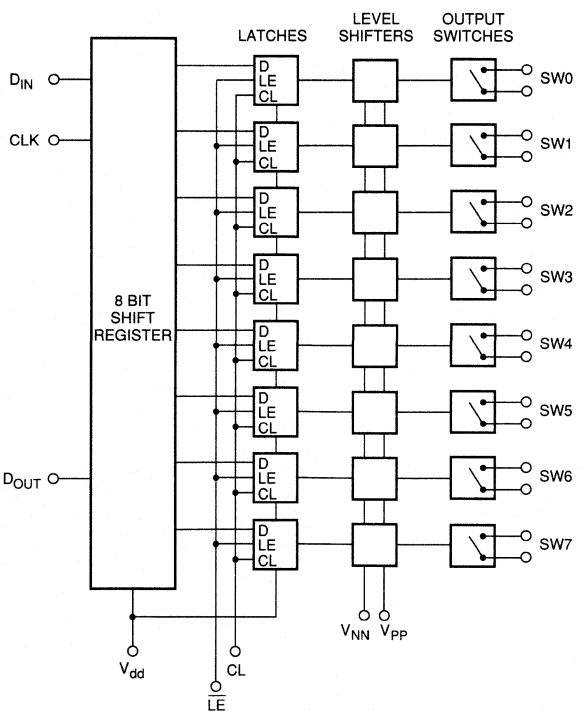




Logic Timing Waveforms



Logic Diagram



Truth Table

D0	D1	D2	D3	D4	D5	D6	D7	$\overline{LE}$	CL	SW0	SW1	SW2	SW3	SW4	SW5	SW6	SW7
L								L	L	OFF							
H								L	L	ON							
	L							L	L		OFF						
	H							L	L		ON						
		L						L	L			OFF					
		H						L	L			ON					
			L					L	L				OFF				
			H					L	L				ON				
				L				L	L					OFF			
				H				L	L					ON			
					L			L	L						OFF		
					H			L	L						ON		
						L		L	L							OFF	
						H		L	L							ON	
							L	L	L								OFF
							H	L	L								ON
X	X	X	X	X	X	X	X	H	L	HOLD PREVIOUS STATE							
X	X	X	X	X	X	X	X	X	H	OFF	OFF	OFF	OFF	OFF	OFF	OFF	OFF

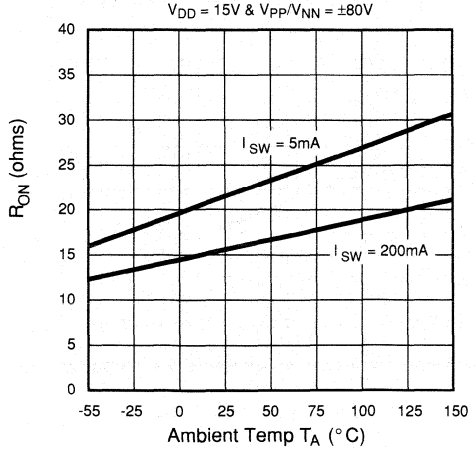
Notes:

1. The eight switches operate independently.
2. Serial data is clocked in on the L→ H transition CK.
3. The switches go to a state retaining their present condition at the rising edge of $\overline{LE}$. When $\overline{LE}$ is low the shift register data flows through the latch.
4. D_{OUT} is high when switch 7 is on.
5. Shift register clockng has no effect on the switch states if $\overline{LE}$ is H.
6. The clear input overrides all other inputs.

Typical Performance Curves

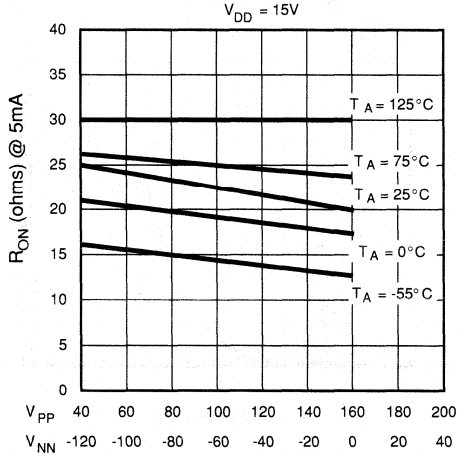
R_{ON} vs Ambient Temp T_A

V_{DD} = 15V & V_{PP}/V_{NN} = ±80V



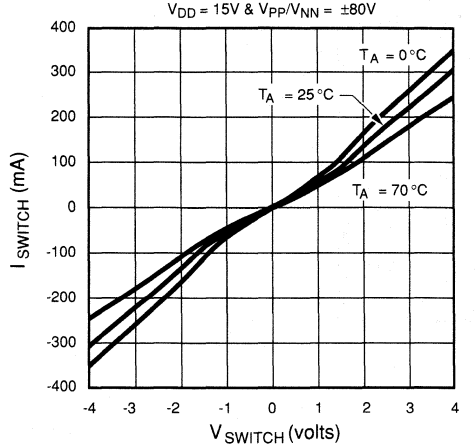
R_{ON} vs V_{PP}/V_{NN}

V_{DD} = 15V



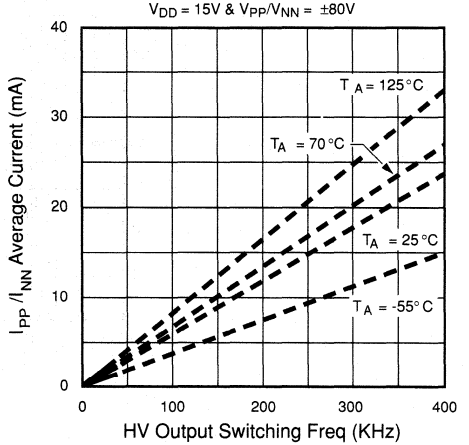
Switch Current vs Switch Voltage Drop

V_{DD} = 15V & V_{PP}/V_{NN} = ±80V



I_{PP}/I_{NN} vs Output Switching Frequency

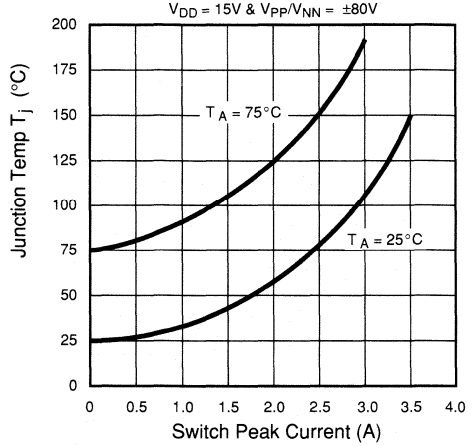
V_{DD} = 15V & V_{PP}/V_{NN} = ±80V



Junction Temp T_j vs Switch Peak Current

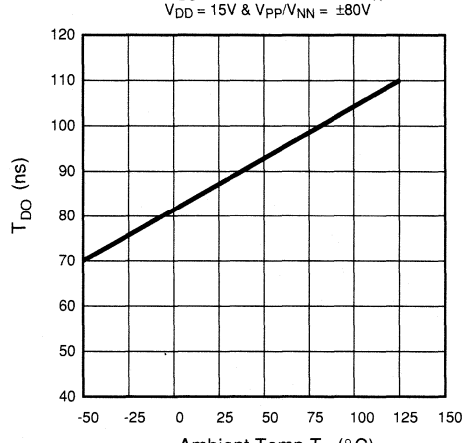
V_{SIG} Freq = 10KHz & Duty Cycle = 0.1%

V_{DD} = 15V & V_{PP}/V_{NN} = ±80V



T_{DO} vs Ambient Temp T_A

V_{DD} = 15V & V_{PP}/V_{NN} = ±80V



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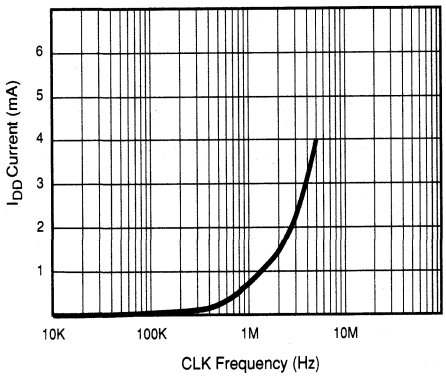
Typical Performance Curves

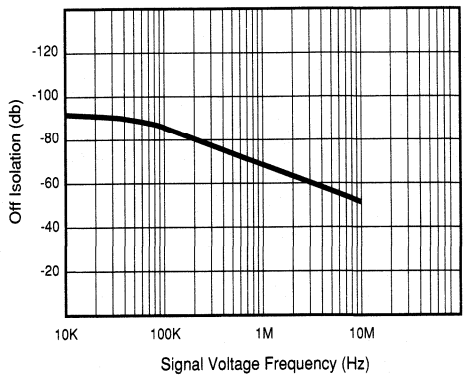
I_{DD} vs CLK Frequency

V_{DD} = 15 V, V_{PP}/V_{NN} = ±80V, T_A = 0°C to 70°C



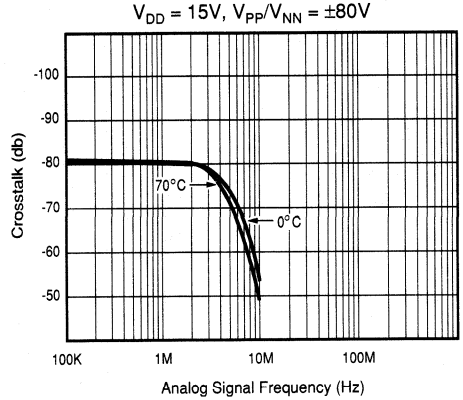
Off Isolation vs Signal Voltage Frequency

V_{DD} = 15V, V_{PP}/V_{NN} = ±80V



Crosstalk vs Analog Signal Frequency

V_{DD} = 15V, V_{PP}/V_{NN} = ±80V



Pin Configurations

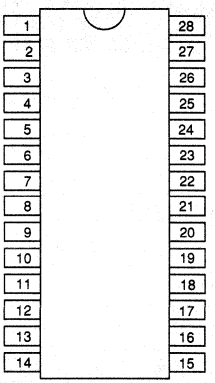
28-Pin DIP

Pin	Function	Pin	Function
1	SW3	15	N/C
2	SW3	16	D_{IN}
3	SW2	17	$\overline{CK}$
4	SW2	18	$\overline{LE}$
5	SW1	19	CL
6	SW1	20	D_{OUT}
7	SW0	21	SW7
8	SW0	22	SW7
9	V_{PP}	23	SW6
10	V_{NN}	24	SW6
11	N/C	25	SW5
12	GND	26	SW5
13	V_{DD}	27	SW4
14	N/C	28	SW4

28-Pin J-Lead

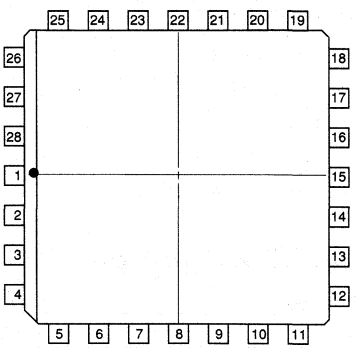
Pin	Function	Pin	Function
1	SW3	15	N/C
2	SW3	16	D_{IN}
3	SW2	17	$\overline{CK}$
4	SW2	18	LE
5	SW1	19	CL
6	SW1	20	D_{OUT}
7	SW0	21	SW7
8	SW0	22	SW7
9	V_{PP}	23	SW6
10	V_{NN}	24	SW6
11	N/C	25	SW5
12	GND	26	SW5
13	V_{DD}	27	SW4
14	N/C	28	SW4

Package Outlines



top view

28-pin DIP



top view

28-pin J-lead Package

64-Channel Serial To Parallel Converter With Open Drain Outputs

Ordering Information

Device	Package Options	
	80-Lead Quad Plastic Gullwing	Die
HV31	HV3137PG	HV3137X

Features

- ☐ HVCMOS® technology
- ☐ Output voltages up to 375V
- ☐ Sink current minimum 1 mA
- ☐ Shift register speed 6 MHz
- ☐ Latched outputs
- ☐ CMOS compatible inputs
- ☐ Forward and reverse shifting options

Absolute Maximum Ratings[1]

Supply voltage, V_{DD}	-0.5V to +9V
Supply voltage, V_{PP}	-0.5V to +375V
Logic input levels	-0.5V to V_{DD} +0.5V
Ground current	0.75A
Continuous total power dissipation[2]	1200mW
Operating temperature range	0°C to +85°C
Storage temperature range	-65°C to +150°C

Notes:
1. All voltages are referenced to GND.
2. For operation above 25°C ambient derate linearly by 15mW/°C up to 85°C.

General Description

The HV31 is a low voltage serial to high voltage parallel converter with open drain outputs. It has been designed especially for use as a driver for electrostatic printers.

This device consists of a 64-bit shift register, 64 latches, latch enable (LE), and output enable (OE). Data is shifted through the shift register on the high to low transition of the clock. When the DIR pin is set high, the HV31 shifts in the counterclockwise direction when viewed from the top of the package. When the DIR pin is set low, the HV31 shifts in the clockwise direction. A serial data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register. Operation of the shift register is not affected by the LE or the OE inputs. Transfer of data from the shift register to the latch occurs when the LE input is high. The data in the latch is stored when LE is low.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Typ	Max	Units	Conditions
I_{DD}	V_{DD} Supply Current				15	mA	f_{CLK} = 6MHz, f_{DATA} = 3MHz $\overline{LE}$ = LOW
I_{DDQ}	Quiescent V_{DD} Supply Current				250	µA	All V_{IN} = 0V
$I_{O(OFF)}$	Off State Output Current at 25°C, per Switch				100	nA	Output high, and at 375V
I_{IH}	High-Level Logic Input Current				10	µA	$V_{IH} = V_{DD}$
I_{IL}	Low-Level Logic Input Current				-10	µA	V_I = 0V
V_{OH}	High-Level Data Out		V_{DD} -1V			V	ID_{OUT} = -100µA
V_{OL}	Low-Level Output	HV_{OUT}			10	V	IHV_{OUT} = +1mA
		Data Out			1	V	ID_{OUT} = +100µA
V_{OC}	HV_{OUT} Clamp Voltage				-3.0	V	I_{OL} = -1mA
C_{HVO}	Output Capacitance per Channel				3	pF	V_{DS} = 100V

AC Characteristics

Symbol	Parameter	Min	Typ	Max	Units	Conditions
f_{CLK}	Clock Frequency			6	MHz	
t_W	Clock Width High or Low	83			ns	
t_{SU}	Data Setup Time Before Clock Falls	35			ns	
t_H	Data Hold Time After Clock Falls	15			ns	
t_{WLE}	Width of Latch Enable Pulse	83			ns	
t_{DLE}	$\overline{LE}$ Delay Time After Falling Edge of Clock	35			ns	
t_{SLE}	$\overline{LE}$ Setup Time Before Falling Edge of Clock	40			ns	
t_{DHL}	Clock Delay Time Data High to Low			135	ns	
t_{DLH}	Clock Delay Time Data Low to High			135	ns	

Recommended Operating Conditions

Symbol	Parameter	Min	Typ	Max	Units
V_{DD}	Logic supply voltage	4.5	5	5.5	V
V_{PP}	High voltage supply	8.0		375	V
V_{IH}	High-level input voltage	3.5		V_{DD}	V
V_{IL}	Low-level input voltage	0		0.8	V
T_A	Operating free-air temperature	0		+85	°C

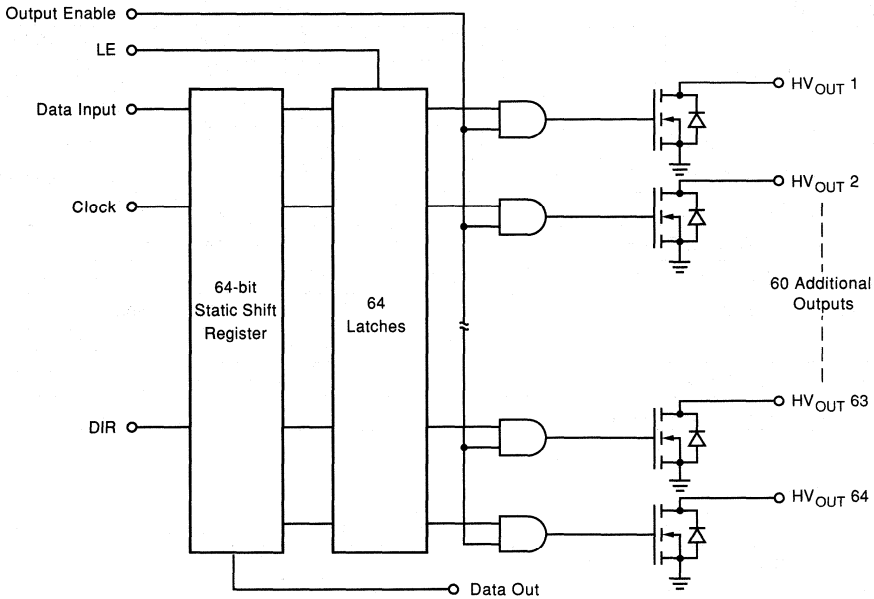
Note:

Power-up sequence should be the following:

1. Connect ground.
2. Apply VDD.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply VPP.

Power-down sequence should be the reverse of the above.

Functional Block Diagram



Function Table

Function	Inputs						Outputs		
	Data	CLK	LE	OE	DIR	Shift Reg 1 2 ... 64	Latch 1 2 ... 64	HV_{OUT} 1 2 ... 64	D_{OUT}
All off	X	X	X	L	X	*...*	*...*	H...H	*
Load S/R	H or L	↓	L	L	H	H or L...Qn → Qn+1	*...*	H...H	*
	H or L	↓	L	L	L	H or L...Qn → Qn-1	*...*	H...H	*
Load Latch	H or L	↓	H	L	X	H or L...*	H or L...*	H...H	*
Output Enable Transparent Latch Mode	X	H or L	H	H	X	H or L...*	H or L...*	L or H...*	*
	H	↓	H	H	X	H...*	H...*	L ...*	*
	L	↓	H	H	X	L ...*	L...*	H...*	*

Notes:

X = Don't care

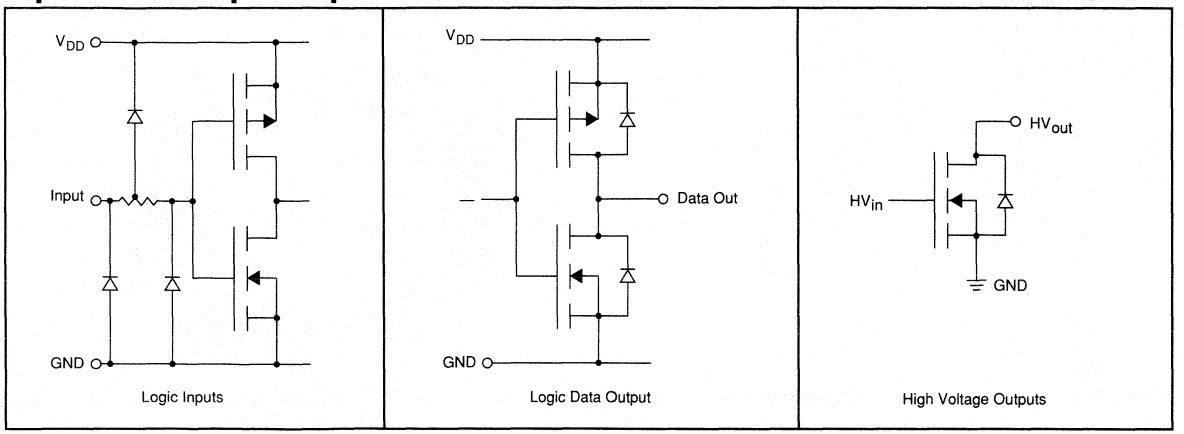
* = Dependent on previous stage's state before the last CLK : High to low transition.

↓ = High to low transition

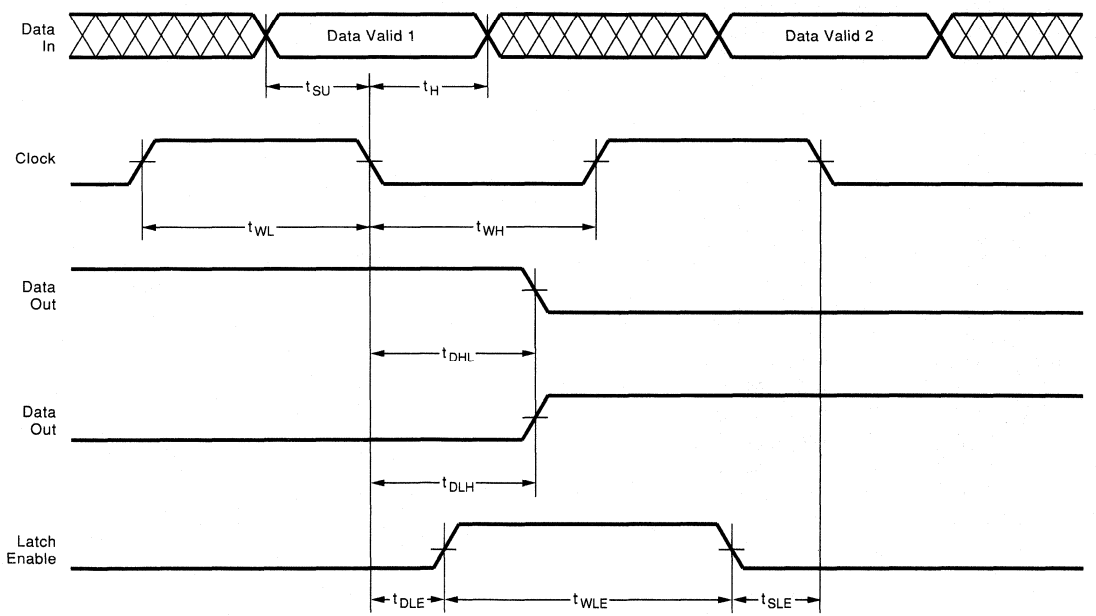
H = High level

L = Low level

Input and Output Equivalent Circuit



Switching Waveforms



Pin Configurations

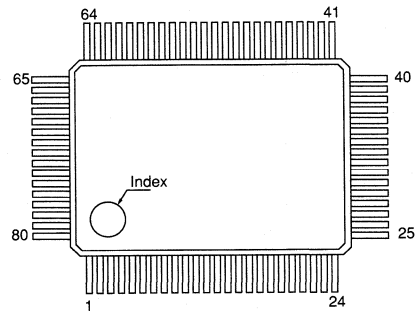
PG and DG Packages

HV31

Pin	Function	Pin	Function
1	GND	41	N/C
2	N/C	42	N/C
3	HV_{OUT} 59/6	43	HV_{OUT} 23/42
4	HV_{OUT} 60/5	44	HV_{OUT} 24/41
5	HV_{OUT} 61/4	45	HV_{OUT} 25/40
6	HV_{OUT} 62/3	46	HV_{OUT} 26/39
7	HV_{OUT} 63/2	47	HV_{OUT} 27/38
8	HV_{OUT} 64/1	48	HV_{OUT} 28/37
9	DIR	49	HV_{OUT} 29/36
10	Data Out	50	HV_{OUT} 30/35
11	CLK	51	HV_{OUT} 31/34
12	GND	52	HV_{OUT} 32/33
13	V_{DD}	53	HV_{OUT} 33/32
14	LE	54	HV_{OUT} 34/31
15	Data In	55	HV_{OUT} 35/30
16	OE	56	HV_{OUT} 36/29
17	HV_{OUT} 1/64	57	HV_{OUT} 37/28
18	HV_{OUT} 2/63	58	HV_{OUT} 38/27
19	HV_{OUT} 3/62	59	HV_{OUT} 39/26
20	HV_{OUT} 4/61	60	HV_{OUT} 40/25
21	HV_{OUT} 5/60	61	HV_{OUT} 23/42
22	HV_{OUT} 6/59	62	HV_{OUT} 24/41
23	N/C	63	N/C
24	HV_{OUT} GND	64	N/C
25	HV_{OUT} 7/58	65	HV_{OUT} 43/22
26	HV_{OUT} 8/57	66	HV_{OUT} 44/21
27	HV_{OUT} 9/56	67	HV_{OUT} 45/20
28	HV_{OUT} 10/55	68	HV_{OUT} 46/19
29	HV_{OUT} 11/54	69	HV_{OUT} 47/18
30	HV_{OUT} 12/53	70	HV_{OUT} 48/17
31	HV_{OUT} 13/52	71	HV_{OUT} 49/16
32	HV_{OUT} 14/51	72	HV_{OUT} 50/15
33	HV_{OUT} 15/50	73	HV_{OUT} 51/14
34	HV_{OUT} 16/49	74	HV_{OUT} 52/13
35	HV_{OUT} 17/48	75	HV_{OUT} 53/12
36	HV_{OUT} 18/47	76	HV_{OUT} 54/11
37	HV_{OUT} 19/46	77	HV_{OUT} 55/10
38	HV_{OUT} 20/45	78	HV_{OUT} 56/9
39	HV_{OUT} 21/44	79	HV_{OUT} 57/8
40	HV_{OUT} 22/43	80	HV_{OUT} 58/7

Note:
Pin designation DIR = H/L
Example: For DIR = H, Pin 3 is HV_{OUT} 59
For DIR = L, Pin 3 is HV_{OUT} 6

Package Outline



top view

80-pin Gullwing Package

Preliminary

32 + 22 Channel Matrix Printhead Driver

Ordering Information

Device	Package Options			
	68 J - Lead Ceramic Quad Flatpack	68 J - Lead Plastic Quad Flatpack	Die	68 J - Lead Ceramic Quad Flatpack (MIL-STD-883 Processed*)
HV33	HV3304DJ	HV3304PJ	HV3304X	RBHV3304DJ

* For Hi-Rel process flows, please refer to page 5-3 in the Databook

Features

- ☐ Separate data (32) and strobe (22) outputs
- ☐ Independant CLK and BLK functions
- ☐ 4MHz opertation (either clock)
- ☐ Latched data outputs
- ☐ 68-pin QFP
- ☐ Mil version available

General Description

The HV33 is dual serial-to-parallel converter chip originally designed for driving printheads. Its dual converters have independent clock inputs and output blanking logic permitting considerable flexibility in driving small matrix arrays with one device.

Absolute Maximum Ratings

Supply voltage, V_{DD}		-0.5V to +7V
Supply voltage, V_{PD}		36V
Supply voltage, V_{PS}		36V
Logic input levels		-0.5V to V_{DD} + 0.5V
Continuous total power dissipation	Ceramic	1900mW
	Plastic	1200mW
Operating temperature range	Ceramic	-40°C to +85°C
	Plastic	0°C to +70°C
Storage temperature range		-65°C to +150°C

Electrical Characteristics (over recommended operating conditions unless noted)

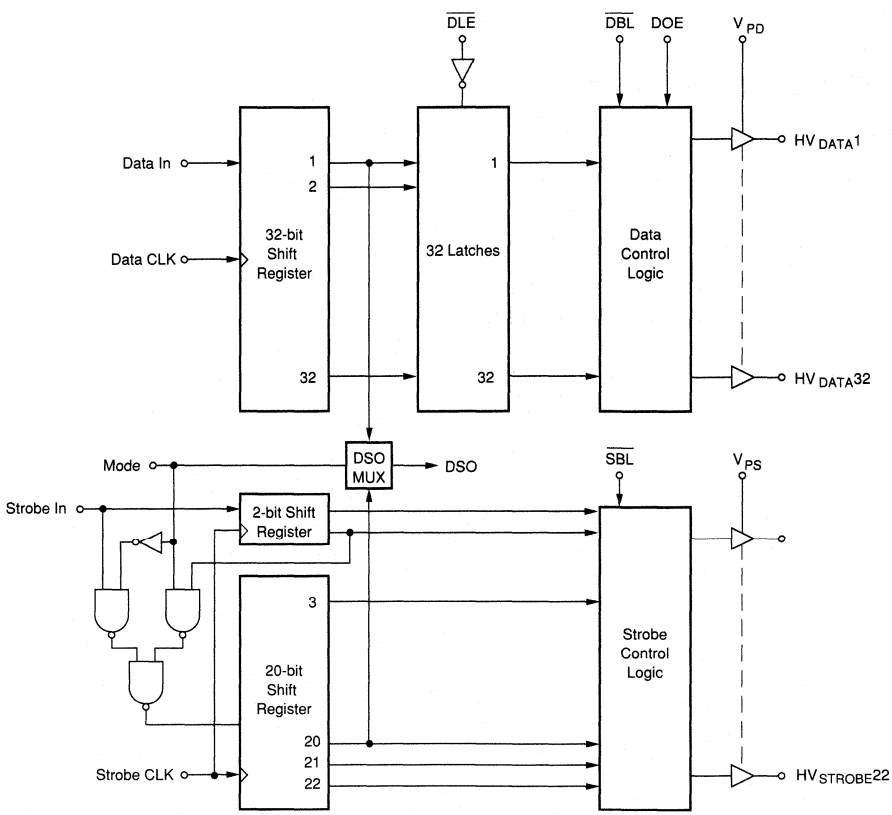
DC Characteristics

Symbol	Parameter	Min	Typ	Max	Units	Conditions
I_{DD}	V_{DD} Supply Current			25	mA	f_{CLK} = 4MHz, f_{DATA} = 2MHz
I_{DDQ}	Quiescent V_{DD} Supply Current			0.25	mA	All V_{IN} = 0V
I_{PP}	High Voltage Supply Current			0.5	mA	Output High and Low
V_{OH}	High-Level Data Out			36	V	I_{OUT} = 4mA
I_{IH}	High-Level Input Current			10	µA	V_{IN} = High
I_{IL}	Low-Level Input Current	-10			µA	V_{IN} = 0V

AC Characteristics

Symbol	Parameter	Min	Typ	Max	Units	Conditions
f_{CLK}	Clock Frequency			4	MHz	
t_W	Clock Width High or Low	125			ns	
t_{SU}	Data Setup Time Before Clock Falls	50			ns	
t_H	Data Hold Time After Clock Falls	20			ns	
t_{DHVS}	Delay from -SBL to HV Strobe			2	µs	250 pF Load
t_{DHVD}	Delay from SCLK/DL to HV Date			2	µs	250 pF Load

Functional Block Diagram



64-Channel Serial To Parallel Converter With Ruggedized High Voltage CMOS Outputs

Ordering Information

Device	Recommended Operating V_{PP} Max	Package Options			
		80-Lead Quad Cerpak Gullwing	80-Lead Quad Plastic Gullwing	80-Lead 35mm TAB Tape	Die
HV34	180V	HV3418DG	HV3418PG	HV3418T	HV3418X

*For Hi-Rel process flows, please refer to page 5-3 in the Databook.

Features

- ☐ HVCMOS® Technology
- ☐ Output voltages up to 180V
- ☐ Low power level shifting
- ☐ Shift register speed
  6MHz @ V_{DD} = 5V
  12MHz @ V_{DD} = 12V
- ☐ Latched data outputs
- ☐ Output polarity and blanking
- ☐ CMOS compatible inputs
- ☐ Forward and reverse shifting options

Absolute Maximum Ratings[1]

Supply voltage, V_{DD}		-0.5V to +15V
Supply voltage, V_{PP}[2]		$V_{DD}$to +200V
Logic input levels		-0.5V to V_{DD} +0.5V
Ground current[3]		1.5A
High voltage supply current[3]		1.3A
Continuous total power dissipation[4]	Ceramic	1900mW
	Plastic	1200mW
Operating temperature range	Ceramic	-40°C to +85°C
	Plastic	0°C to +70°C
Storage temperature range		-65°C to +150°C

Notes:
1. All voltages are referenced to GND.
2. These devices have been designed to be used in applications which either switch the V_{PP} supply to ground before changing the state of the high voltage outputs or limit the current through each output.
3. Connection to all power and ground pads is required. Duty cycle is limited by the total power dissipated in the package.
4. For operation above 25°C ambient derate linearly to 85°C at 15mW/°C.

General Description

The HV34 is a low voltage serial to high voltage parallel converters with push-pull outputs. This device has been designed for use as a printer drivers for ink-jet applications. It can also be used in any application requiring multiple output high voltage, low current sourcing and sinking capabilities.

The device consists of a 64-bit shift register, 64 latches, and control logic to perform the polarity select and blanking of the outputs. A DIR pin controls the direction of data shift through the device. With DIR grounded, D_{IO} is Data-In and D_{OI} is Data-Out; data is shifted from $HV_{OUT}1$ to $HV_{OUT}64$. When DIR is at logic high, D_{OI} is Data-In and D_{IO} is Data-Out: data is then shifted from $HV_{OUT}64$ to $HV_{OUT}1$. Data is shifted through the shift register on the low to high transition of the clock. Data output buffers are provided for cascading devices. Operation of the shift register is not affected by the $\overline{LE}$ (latch enable), $\overline{BL}$ (blanking), or the $\overline{POL}$ (polarity) inputs. Transfer of data from the shift register to the latch occurs when the $\overline{LE}$ (latch enable) is high. The data in the latch is stored during $\overline{LE}$ transition from high to low.

Electrical Characteristics (V_{PP} = 180, V_{DD} = 12V, T_A = 25°C)

DC Characteristics

Symbol	Parameter		Min	Typ	Max	Units	Conditions
I_{DD}	V_{DD} Supply Current				25	mA	f_{CLK} = 12MHz, f_{DATA} = 12MHz $\overline{LE}$ = LOW
I_{DDQ}	Quiescent V_{DD} Supply Current				200	µA	All V_{IN} = 0V or $V_{DD}V_{DD}$
I_{PP}	High Voltage Supply Current				0.50	mA	V_{PP} = 180V All outputs high
					0.50	mA	V_{PP} = 180V All outputs low
I_{IH}	High-Level Logic Input Current				10	µA	V_{IH} = V_{DD}
I_{IL}	Low-Level Logic Input Current		-10			µA	V_I = 0V
V_{OH}	High-Level Output	HV_{OUT}	155			V	V_{PP} = 180V, IHV_{OUT} = -5mA
		Data Out	V_{DD} -1V			V	ID_{OUT} = -100µA
V_{OL}	Low-Level Output	HV_{OUT}			25	V	V_{PP} = 180V, IHV_{OUT} = +5mA
		Data Out			1.0	V	ID_{OUT} = +100µA
V_{OC}	HV_{OUT} Clamp Voltage				V_{PP} +1.5	V	I_{OL} = +5mA
					-1.5	V	I_{OL} = -5mA

AC Characteristics[1,2] (For V_{DD} = 12V: values in parenteses are for V_{DD} =5V; V_{PP} = 180V, T_A = 25°C)

Symbol	Parameter	Min	Typ	Max	Units	Conditions
f_{CLK}	Clock Frequency	12(6)			MHz	
t_W	Clock Width High and Low	40(62)			ns	
		35(42)			ns	
t_{SU}	Data Setup Time Before Clock Rises	25(35)			ns	
t_H	Data Hold Time After Clock Rises	10(30)			ns	
t_{WLE}	Width of Latch Enable Pulse	62(80)			ns	
t_{DLE}	$\overline{LE}$ Delay Time Rising Edge of Clock	25(35)			ns	
t_{SLE}	$\overline{LE}$ Setup Time Before Rising Edge of Clock	30(40)			ns	
t_{ON}, t_{OFF}	Time from Latch Enable to HV_{OUT}			1(1.5)	µs	C_L = 20pF
t_{DHL}	Delay Time Clock to Data High to Low			50(80)	ns	C_L = 20pF
t_{DLH}	Delay Time Clock to Data Low to High			50(80)	ns	C_L = 20pF
t_r, t_f	All Logic Inputs			5	ns	

Notes:
1. Shift register speed can be as low as DC as long as Data Set-up and Hold Time meet the spec.
2. AC Characteristics are guaranteed only under V_{DD} = 12V and V_{DD} = 5V.

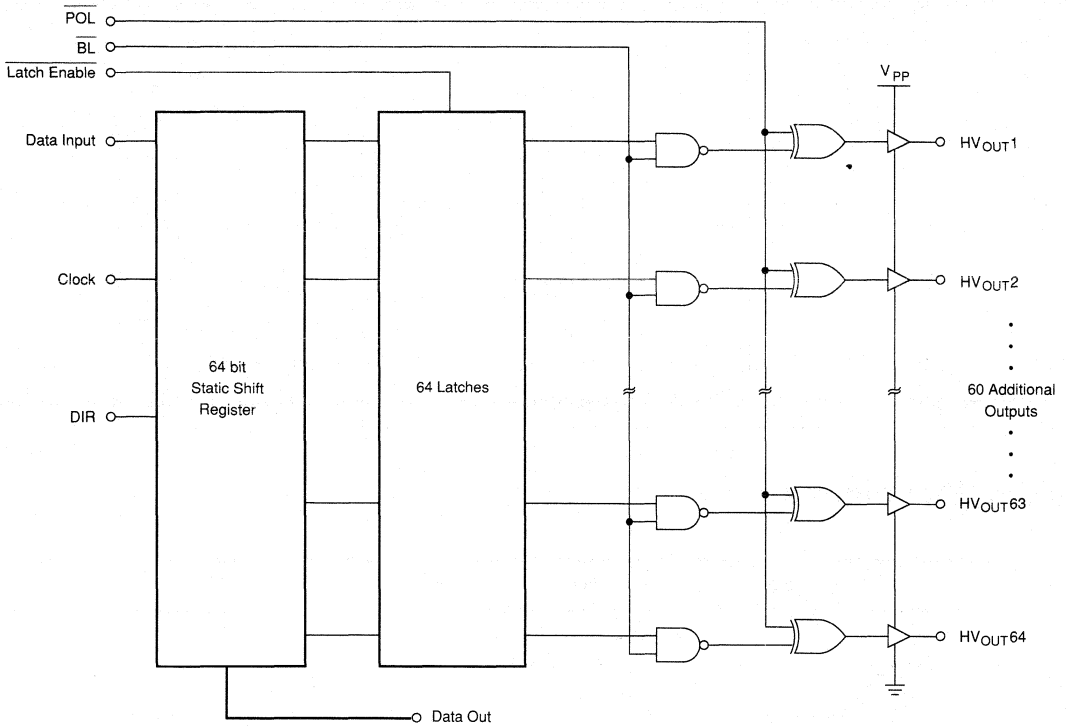
Recommended Operating Conditions

Symbol	Parameter		Min	Typ	Max	Units
V_{DD}	Logic supply voltage	V_{DD} = 5V	4.5	5.0	5.5	V
		V_{DD} =12V	10.8	12.0	13.2	V
V_{PP}	High voltage supply		60		180	V
V_{IH}	High-level input voltage		V_{DD} -0.9		V_{DD}	V
V_{IL}	Low-level input voltage		0		0.9	V
T_A	Operating free-air temperature		0		+70	°C

Note:
Power-up sequence should be the following:
1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

Functional Block Diagram

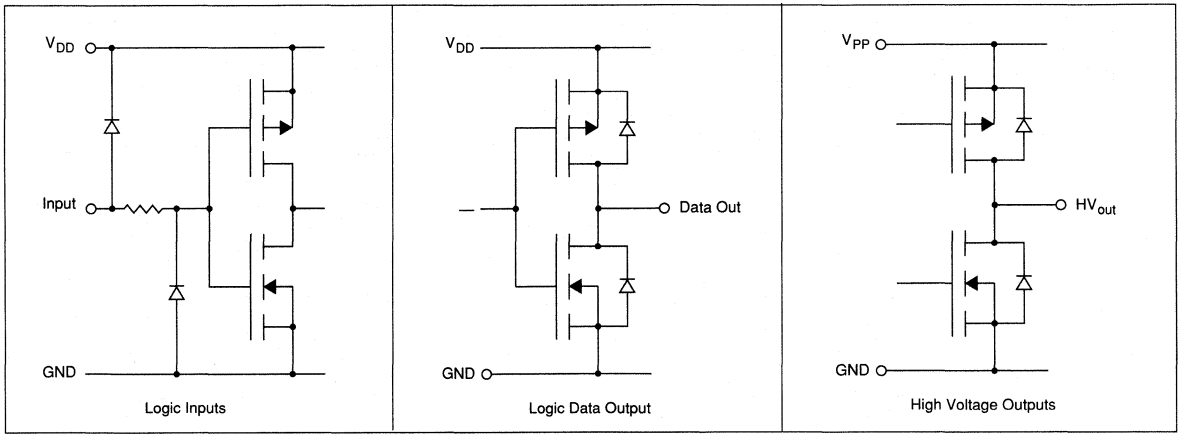


Function Table

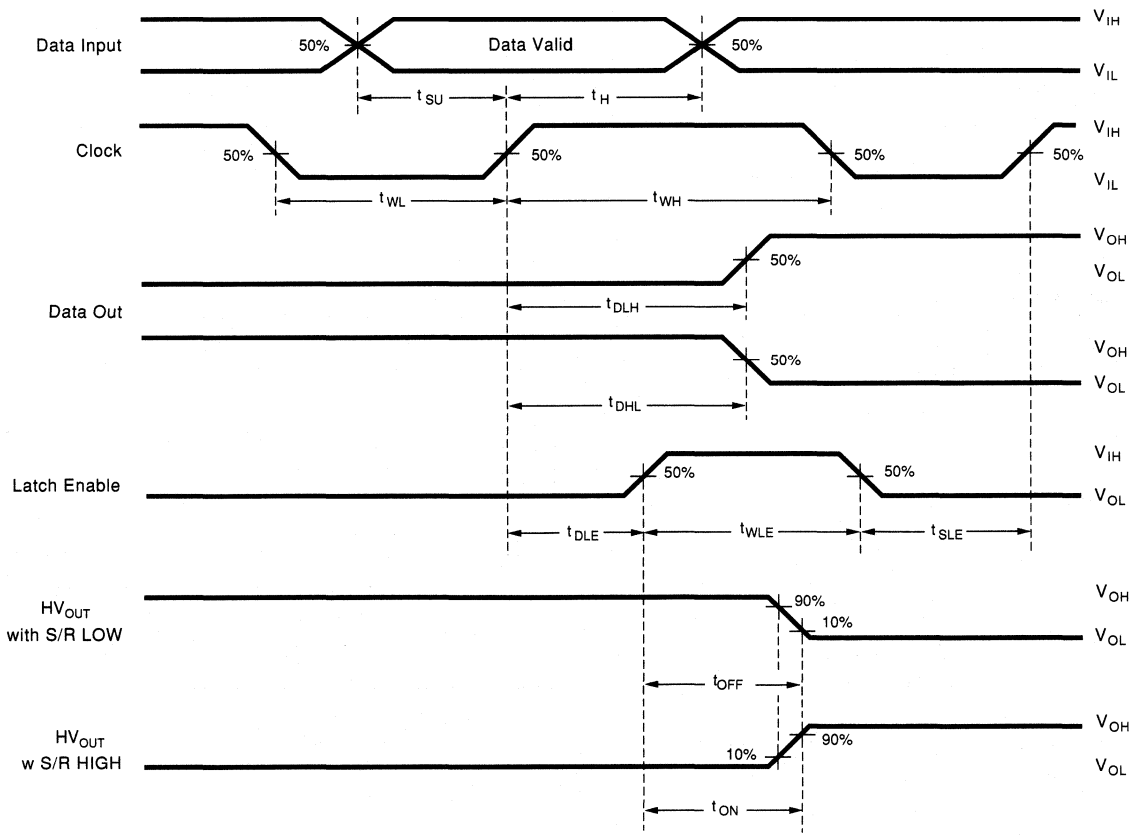
Function	Inputs					Outputs		
	Data	CLK	$\overline{LE}$	$\overline{BL}$	$\overline{POL}$	Shift Reg 1 2...64	HV Outputs 1 2...64	Data Out *
All on	X	X	X	L	L	* *...*	H H...H	*
All off	X	X	X	L	H	* *...*	L L...L	*
Invert mode	X	X	L	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Load S/R	H or L	↑	L	H	H	H or L *...*	* *...*	*
Load Latches	X	H or L	↓	H	H	* *...*	* *...*	*
	X	H or L	↓	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Transparent Latch mode	L	↑	H	H	H	L *...*	L *...*	*
	H	↑	H	H	H	H *...*	H *...*	*

Notes:
H = high level, L = low level, X = irrelevant, ≠ = low-to-high transition.
* = dependent on previous stage's state before the last CLK or last $\overline{LE}$ high,

Input and Output Equivalent Circuits



Switching Waveforms

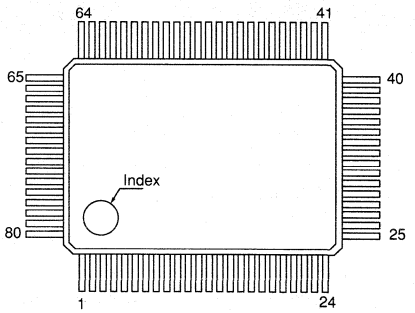


Pin Configurations

HV34

Pin	Function	Pin	Function
1	HV_{OUT} 41	41	HV_{OUT} 1
2	HV_{OUT} 42	42	HV_{OUT} 2
3	HV_{OUT} 43	43	HV_{OUT} 3
4	HV_{OUT} 44	44	HV_{OUT} 4
5	HV_{OUT} 45	45	HV_{OUT} 5
6	HV_{OUT} 46	46	HV_{OUT} 6
7	HV_{OUT} 47	47	HV_{OUT} 7
8	HV_{OUT} 48	48	HV_{OUT} 8
9	HV_{OUT} 49	49	HV_{OUT} 9
10	HV_{OUT} 50	50	HV_{OUT} 10
11	HV_{OUT} 51	51	HV_{OUT} 11
12	HV_{OUT} 52	52	HV_{OUT} 12
13	HV_{OUT} 53	53	HV_{OUT} 13
14	HV_{OUT} 54	54	HV_{OUT} 14
15	HV_{OUT} 55	55	HV_{OUT} 15
16	HV_{OUT} 56	56	HV_{OUT} 16
17	HV_{OUT} 57	57	HV_{OUT} 17
18	HV_{OUT} 58	58	HV_{OUT} 18
19	HV_{OUT} 59	59	HV_{OUT} 19
20	HV_{OUT} 60	60	HV_{OUT} 20
21	HV_{OUT} 61	61	HV_{OUT} 21
22	HV_{OUT} 62	62	HV_{OUT} 22
23	HV_{OUT} 63	63	HV_{OUT} 23
24	HV_{OUT} 64	64	HV_{OUT} 24
25	V_{PP}	65	HV_{OUT} 25
26	D_{OUT}	66	HV_{OUT} 26
27	N/C	67	HV_{OUT} 27
28	N/C	68	HV_{OUT} 28
29	$\overline{BL}$	69	HV_{OUT} 29
30	$\overline{PL}$	70	HV_{OUT} 30
31	V_{DD}	71	HV_{OUT} 31
32	DIR	72	HV_{OUT} 32
33	LGND	73	HV_{OUT} 33
34	DGND	74	HV_{OUT} 34
35	N/C	75	HV_{OUT} 35
36	N/C	76	HV_{OUT} 36
37	CLK	77	HV_{OUT} 37
38	$\overline{LE}$	78	HV_{OUT} 38
39	DIN	79	HV_{OUT} 39
40	V_{PP}	80	HV_{OUT} 40

Package Outline



top view

80-pin Gullwing Package

Preliminary

32-Channel Gray-Shade Display Column Driver

Ordering Information

Device	Package Options			
	64-Lead 3-sided Plastic Gullwing	64-Lead 3-sided Ceramic Gullwing	Die	64-Lead 3-sided Ceramic Gullwing (MIL-STD-883 Processed)
HV38	HV3806PG	HV3806DG	HV3806X	RBHV3806DG

* For Hi-Rel process flows, refer to page 5-3 of the Databook.

Features

- ☐ 5V CMOS inputs
- ☐ Up to 60V modulation voltage
- ☐ Capable of 16 levels of gray shading
- ☐ 16MHz data throughput rate
- ☐ 32 Outputs per device (can be cascaded)
- ☐ Minimum 15 mA high-voltage output source/sink capability
- ☐ Pin-programmable shift direction (DIR)
- ☐ D/A conversion can be performed in as little as 3.2µs
- ☐ Diodes in output structure allow usage in energy recovery systems
- ☐ Integrated high-voltage CMOS technology
- ☐ Available in 3-sided 64-lead gullwing package or as dice

Absolute Maximum Ratings

Supply voltage, V_{DD}[1]		-0.5V to +7.5V
Supply voltage, V_{PP1}/V_{PP2}		-0.5V to +60V
Logic input levels[1]		-0.5 to V_{DD} + 0.5V
Ground current[2]		1.5A
Continuous total power dissipation[3]	Plastic	1200mW
	Ceramic	1500mW
Operating temperature range		-40°C to +85°C
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. All voltages are referenced to V_{SS}.
2. Duty cycle is limited by the total power dissipated in the package.
3. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

General Description

The HV38 is a 32-channel column driver IC designed for gray-shade display use. A bidirectional shift register working on both clock edges is used to index input data, in groups of 4, into a set of data latches. These are compared to the contents of a master binary counter. Each time the master counter begins to increment, a hold capacitor (C_H) on each channel is charged until the contents of the data latches is matched by that in the counter. Each channel's C_H thus is charged to an individual level, V_H, which is then transferred to the output by a source-follower structure that allows both sourcing and sinking of output current.

DIR is a shift-direction-select pin which has been provided to allow the user to interchange the shift register data input. When the DIR input is high, data is shifted in thru D1 to D4 in ascending order from $HV_{OUT}1$ to $HV_{OUT}32$. When the DIR input is low, data is shifted in descending order from $HV_{OUT}32$ to $HV_{OUT}1$.

In the HV38, the ramp generator circuitry (V_R) obtains its (low-current) bias from V_{PP1}. This allows the output bias, V_{PP2}, to be ramped down to zero when output current is not required, thus saving energy.

Electrical Characteristics (at 25°C, unless otherwise specified)

Low-Voltage DC Characteristics

Symbol	Parameter	Min	Typ[1]	Max	Units	Conditions
V_{DD}	Low-voltage supply	4.5	5.0	5.5	V	f_{SC} = 8MHz
I_{DD}	V_{DD} supply current (active)		6.0	10.0	mA	f_{CC} = 6MHz F_{DATA} = 8MHz
I_{DDS}	V_{DD} supply current (standby)			100	µA	All V_{IN} = 0V, V_{DD} = min
V_{IH}	High-level input voltage	V_{DD} -1		V_{DD}	V	
V_{IL}	Low-level input voltage	0		1	V	
I_{IH}	High-level input current		1.0	50	µA	V_{IH} = V_{DD}
I_{IL}	Low-level input current		-1.0	-50	µA	V_{IL} = 0V
C_{IN}	Input capacitance (data, LC, SC, CC)			10	pF	V_{IN} = 0V, f = 1MHz
T_A	Operating free-air temperature	-40		85	°C	
V_{OH}	High-level output voltage	V_{DD} -1			V	I_{OH} = -4mA, V_{DD} = min
V_{OL}	Low-level output voltage			0.4	V	I_{OL} = 4mA, V_{DD} = min
I_{OH}	High-level output current			-4.0	mA	
I_{OL}	Low-level output current			4.0	mA	

Note 1. All typical values are at V_{DD} = 5.0V.

High-Voltage DC Characteristics

Symbol	Parameter	Min	Typ	Max	Units	Conditions
V_{PP}	High-voltage supply	-0.3		60	V	
I_{PP}	V_{PP} supply current			100	µA	V_{PP} = 60V, outputs high or low, no load
V_R	Ramp voltage	0		V_{PP}-2	V	
I_{AOH} max	Maximum high-voltage analog output source current[1]			-15	mA	V_{PP} = 60V
I_{AOH}	High-voltage analog output source current[1]	-10			mA	V_{PP} = 60V V_R = 30V, V_{AO} = 25V
		-100			µA	V_{AO} = 28.75V
I_{AOL} max	Maximum high-voltage analog output sink current[2]			15	mA	V_{PP} = 60V
I_{AOL}	High-voltage analog output sink current[2]	10			mA	V_{PP} = 60V V_R = 30V, V_{AO} = 25V
		100			µA	V_{AO} = 31.25V

Notes:
1. Either by N-CH transistor or P-CH output diode.
2. Either by P-CH transistor or N-CH output diode.
3. Power-up sequence should be the following:
   1. Connect ground.
   2. Apply V_{DD}.
   3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
   4. Apply V_{PP}.

   Power-down sequence should be the reverse of the above.

Electrical Characteristics

AC Characteristics (V_{DD} = 5V, T_A = 25°C)

Logic Timing

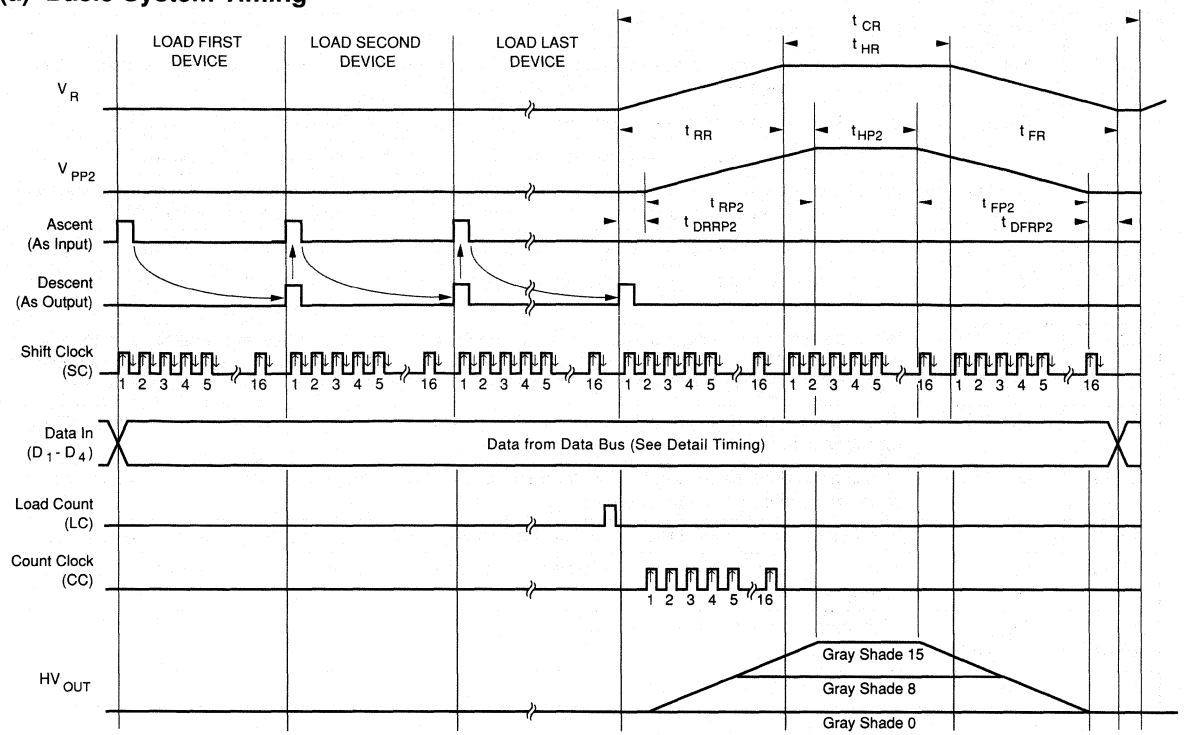
Symbol	Parameter	Min	Typ	Max	Units	Conditions
f_{SC}	Shift clock operating frequency			8	MHz	
f_{DIN}	Data-in frequency			16	MHz	
t_{SS}	Ascent/Descent pulse to shift clock setup time		20		ns	
t_{HS}	Ascent/Descent pulse to shift clock hold time		40		ns	
t_{WA}	Ascent pulse width		55		ns	
t_{DS}	Data to shift clock setup time		0		ns	
t_{DH}	Data to shift clock hold time		50		ns	
t_{WD}	Data-in pulse width		55		ns	
t_{WLC}	Load count pulse width		200		ns	
t_{DLCR}	Load count to ramp delay			100	ns	
t_{DLCC}	Load count to count clock delay		70		ns	
t_{WLC}	Load count pulse width		200		ns	
t_{DSL}	Shift clock to load count delay time	TBD	200		ns	
t_{CSC}	Shift clock cycle time			125	ns	
t_{CCC}	Count clock cycle time	190			ns	
t_{WCC}	Count clock pulse width	90			ns	

V_{RAMP} Timing

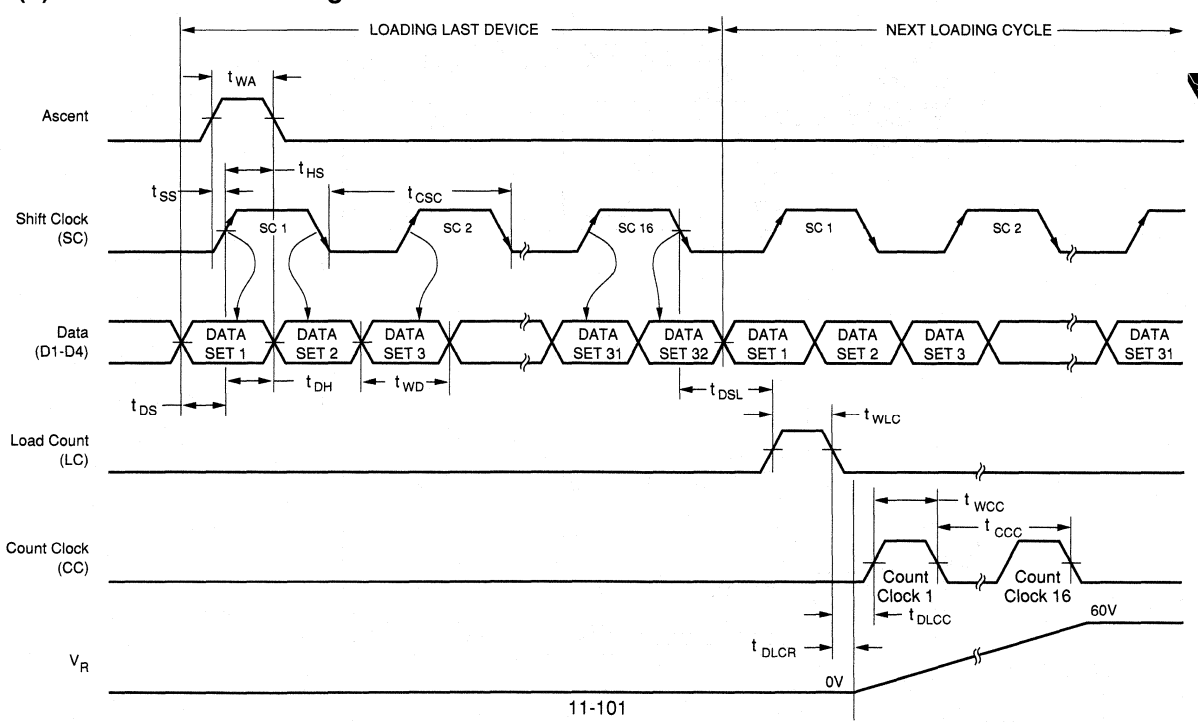
Symbol	Parameter	Min	Typ	Max	Units	Conditions
t_{CR}	Cycle time of ramp signal	8			µs	
t_{RR}	Ramp rise time	3			µs	
t_{HR}	Ramp hold time	2			µs	
t_{FR}	Ramp fall time	3			µs	
t_{DRRP2}	Rise time delay from V_R to V_{PP2}	TBD			µs	
t_{HP2}	V_{PP2} hold time	TBD			µs	
t_{RP2}	V_{PP2} ramp-up time	TBD			µs	
t_{FP2}	V_{PP2} ramp-down time	TBD			µs	
t_{DFRP2}	Fall time delay from V_R to V_{PP2}	TBD			µs	

Timing Diagrams

(a) Basic System Timing



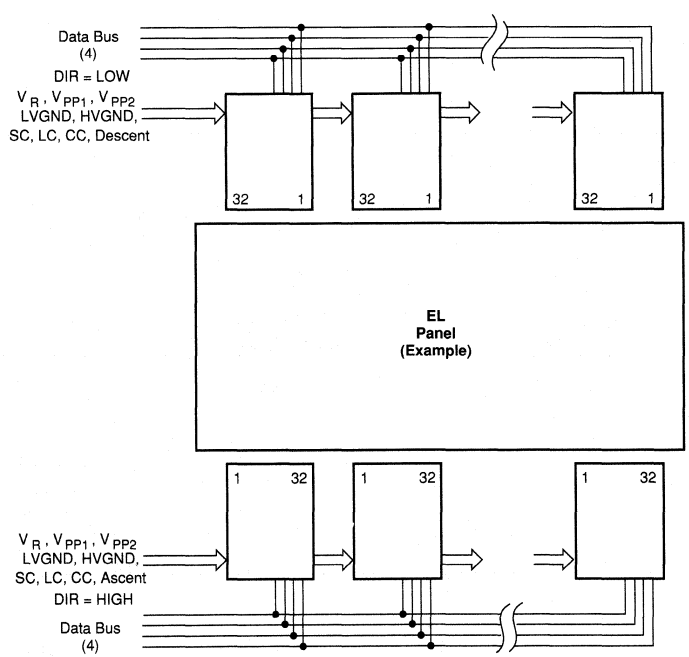
(b) Detailed Device Timing



Pin definitions

Pin #	Name	Function
27-30	D1-D4	Inputs for binary-format parallel data
26	Shift clock	Triggers data on both rising and falling edges. This implies that the data rate is always twice the clock rate (data rate = 16MHz max if clock rate = 8MHz max)
22	Ascent	Input pin for the Ascent pulse (when DIR is high). Output pin for Descent pulse (when DIR is low).
43	Descent	Input pin for the Descent pulse (when DIR is low). Output pin for the Ascent pulse (when DIR is high).
40	Load Count	Input for a pulse whose rising edge causes data from the input latches to enter the comparator latches, and whose falling edge initiates the conversion of this binary data to an output level (D-to-A).
42	Count Clock	Input to the count clock generator whose increments are compared to the data in the comparator latches.
18,47	V_R	High-voltage ramp input for charging the output stage hold capacitors (C_H). This input can be linear or non-linear as desired.
32	DIR	When this pin is connected to V_{DD}, input data is shifted in ascending order, i.e. corresponding to $HV_{OUT}1$ to $HV_{OUT}32$. When connected to LVGND, input data is shifted in descending order, i.e. corresponding to $HV_{OUT}32$ to $HV_{OUT}1$.
31	LVGND	This is ground for the logic section. It may be connected to the HVGND pin, or kept separate in energy recovery circuits.
20,45	HVGND	This is ground for the high-voltage (output) section. It may be connected to the LVGND pin, or kept separate in energy recovery circuits.
19,46	$V_{PP}1$	This input biases the level translators and the P-channel transistors that charge the holding caps (C_H).
17,48	$V_{PP}2$	This input biases the output source followers. It can be set equal to $V_{PP}1$ or can be ramped (especially in energy recovery schemes).
1-16 49-64	$HV_{OUT}1$- $HV_{OUT}32$	High-voltage source-follower outputs.
33	V_{DD}	Low-voltage logic power supply.

Typical EL Panel Connections



Theory of Operation

The HV38 has two primary functions:

1) Loading data from the data bus and,
2) Gray-shade conversion
   (converting latched data to output voltages).

Since the device was developed initially for electroluminescent displays, the operation will be described in terms that pertain to that technology. As shown by the Typical EL Drive Scheme, several HV38 packages are mounted at the top and bottom of a display panel. Data exists on a 4-bit bus (adjacent PC board traces) at top and bottom. The D1 through D4 inputs of each chip take data from the bus when either an ASCENT or DESCENT pulse is present at the chip. These pulses therefore act as a combination CHIP SELECT and LOCATION STROBE. Because of the way the chip HV_{OUT} pins are sequenced, data on the bus at the bottom of the display panel will be entered into the leftmost chip as $HV_{OUT}1$, $HV_{OUT}2$, etc. up to $HV_{OUT}32$. The ASCENT pulse will accomplish this with DIR = High.

Loading Data from Data Bus

Here is the full data-entry sequence:

1) The microcontroller puts data on the bus (4 bits)
2) To enter the data into the 32 sets of 4 latches on the first chip, the shift clock rises. This positive transition is combined with the ASCENT pulse (sometimes called a SEED BIT) and is generated only once to strobe the data into the first set of latches. (These latches eventually send data to the $HV_{OUT}1$). The data on the bus then changes, the shift clock falls, and this negative transition is combined with the ASCENT pulse, which is now propagated internally, to strobe the new data into the next set of 4 latches (which will end up as $HV_{OUT}2$). This internal ASCENT pulse therefore runs at twice the shift clock rate.
3) When the last set of 4 latches in the first chip has been loaded ($HV_{OUT}32$), the ASCENT pulse leaves chip 1 and enters chip 2. The exit pin is called DESCENT and the chip 2 entry pin is ASCENT. For chips at the top of the panel things are reversed: DIR is low, entry pins are DESCENT and exit pins are ASCENT, because the data-into-latches sequence is in descending order, $HV_{OUT}32$ down to $HV_{OUT}1$.
4) The buses may of course be separate, and data can be strobed in on an interleaved basis, etc. but those complications will be left to systems designers.

When data has been loaded into all 32 outputs of all chips (top and bottom of the display panel), the load count pin is pulsed. On its rising transition, all the data in the input latches is transferred to a like number of comparator latches, (thus leaving the data latches ready to receive new data during the following operations). After the transfer, the load count pin is brought low. This transition begins the events that convert the binary data into a gray-shade level.

Gray-shade Conversion

1) The COUNT CLOCK is started. This external signal is applied to the COUNT CLOCK pin, causing the counter on each chip to increment from binary 0000 to 1111 (0 to 15).
2) At the same time, the V_R voltage is applied to all chips, via charging transistors, causing the HOLD CAPACITORS (C_H) on each output to experience a rise in voltage.
3) If each set of comparator latches held binary 1111 (a count of 15), the V_R voltage would charge each C_H to the full value of V_R. The voltage followers on each output would thus present this level as a maximum-brightness output to the panel.
4) On the other hand, if the count in the comparator latches is less than maximum, when the COUNT CLOCK had incremented the master counter to a value that matched the latch value, that particular charging transistor would be cut off, leaving that C_H at some other value of voltage (gray-shade level).

It should be clear that :

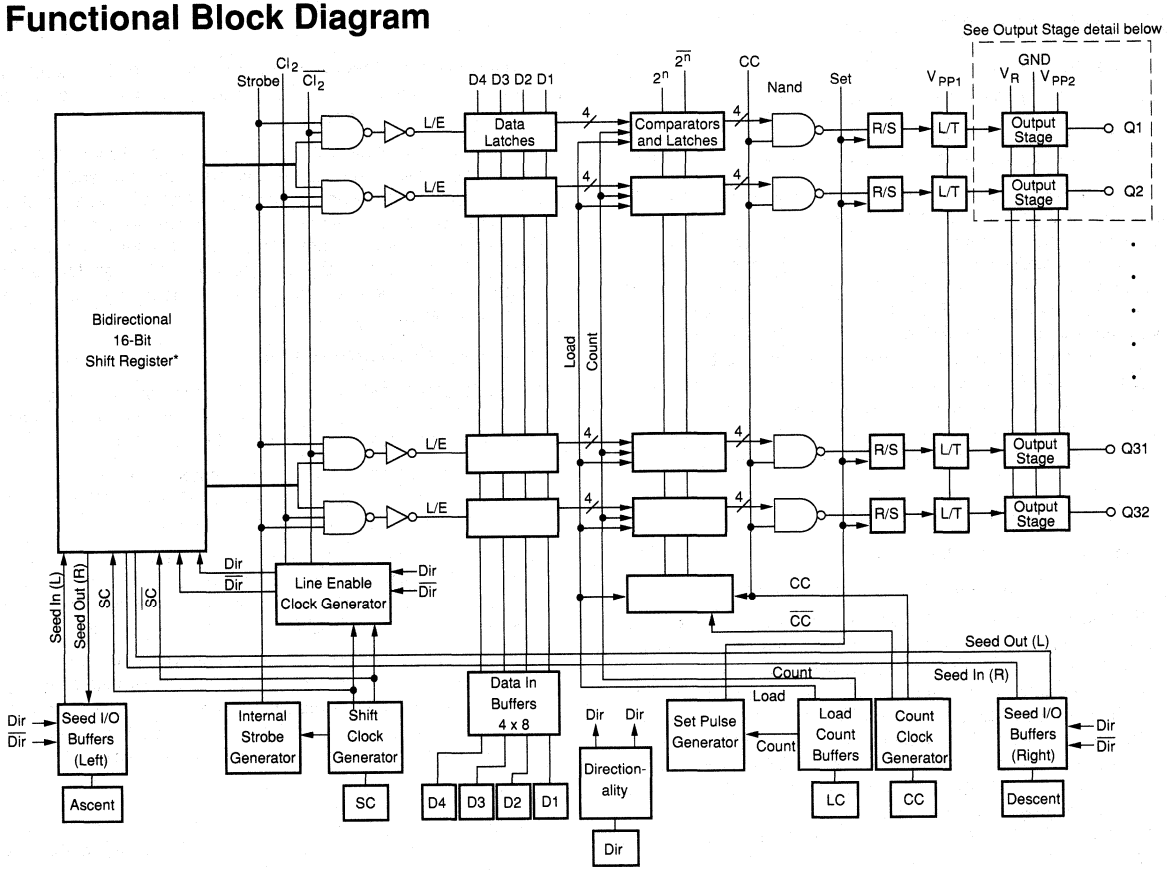
a) Data continues until all latches in all chips are loaded. The shift clock and the internal ASCENT/DESCENT pulses last for the same duration.

b) Count clock endures for 16 counts after load count goes low.

Function Table

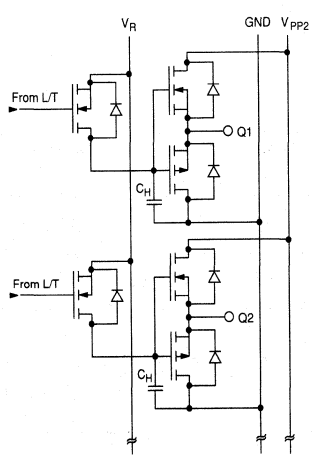
Sequence	Function	DIR	Data-In (D1 - D4)	Ascent	Descent	Shift Clock	Load Count	Count Clock	V_R
1	Shift Data from $HV_{OUT}1$ to 32	H	H/L		Output		L	L	L
2	Shift Data from $HV_{OUT}32$ to 1	L	H/L	Output			L	L	L
3	Load Shift Register	X	X	Pre-defined by 1 or 2			L	L	L
4	Load Counter	X	X			L		L	L
5	Counting/Voltage Conversion	X	X			L	L		Initiates V_{RAMP}

Functional Block Diagram



* Uses both clock edges.

Output Stage Detail

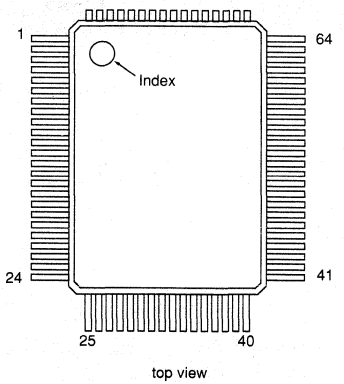


Pin Configuration

64-Pin PG Package

Pin	Function	Pin	Function	Pin	Function
1	HV_{OUT} 1	23	NC	45	HVGND
2	HV_{OUT} 2	24	NC	46	V_{PP1}
3	HV_{OUT} 3	25	NC	47	V_R
4	HV_{OUT} 4	26	Shift Clock	48	V_{PP2}
5	HV_{OUT} 5	27	D_4	49	HV_{OUT} 17
6	HV_{OUT} 6	28	D_3	50	HV_{OUT} 18
7	HV_{OUT} 7	29	D_2	51	HV_{OUT} 19
8	HV_{OUT} 8	30	D_1	52	HV_{OUT} 20
9	HV_{OUT} 9	31	LVGND	53	HV_{OUT} 21
10	HV_{OUT} 10	32	DIR	54	HV_{OUT} 22
11	HV_{OUT} 11	33	V_{DD}	55	HV_{OUT} 23
12	HV_{OUT} 12	34	NC	56	HV_{OUT} 24
13	HV_{OUT} 13	35	NC	57	HV_{OUT} 25
14	HV_{OUT} 14	36	NC	58	HV_{OUT} 26
15	HV_{OUT} 15	37	NC	59	HV_{OUT} 27
16	HV_{OUT} 16	38	NC	60	HV_{OUT} 28
17	V_{PP2}	39	NC	61	HV_{OUT} 29
18	V_R	40	Load Count	62	HV_{OUT} 30
19	V_{PP1}	41	NC	63	HV_{OUT} 31
20	HVGND	42	Count Clock	64	HV_{OUT} 32
21	NC	43	DESCENT		
22	ASCENT	44	NC		

Package Outline



3-sided Plastic QFP 64-pin Gullwing Package

Gray Shade Decoding Scheme

Brightest Shade No.	D4	D3	D2	D1	
15	1	1	1	1	Brightest
14	1	1	1	0	
13	1	1	0	1	
12	1	1	0	0	
11	1	0	1	1	
10	1	0	1	0	
9	1	0	0	1	
8	1	0	0	0	
7	0	1	1	1	
6	0	1	1	0	
5	0	1	0	1	
4	0	1	0	0	
3	0	0	1	1	
2	0	0	1	0	
1	0	0	0	1	
0	0	0	0	0	Dimmest

Preliminary

High Voltage Analog Switches

Ordering Information

Function			Dual SPST	Dual SPDT	Dual DPST	Dual SPST
Analog Signal Range			V_{NN} to V_{PP}	V_{NN} to V_{PP}	V_{NN} to V_{PP}	V_{NN} to V_{PP}
$RDS_{(ON)}$			110 ohms	110 ohms	110 ohms	55 ohms
Order No. and Part Type	**Package Type**	**Temp Range**				
	16-lead CERDIP, Hi-Rel†	-55°C to +125°C	RBHV341D	RBHV343D	RBHV345D	RBHV348D
	16-lead CERDIP, Mil-Temp	-55°C to +125°C	HV341D	HV343D	HV345D	HV348D
	16-lead CERDIP	-20°C to + 85°C	HV341MD	HV343MD	HV345MD	HV348MD
	16-lead small outline*	-20°C to + 85°C	HV341MWG	HV343MWG	HV345MWG	HV348MWG
	16-lead small outline*	0°C to + 70°C	HV341WG	HV343WG	HV345WG	HV348WG
	16-lead plastic DIP	0°C to + 70°C	HV341P	HV343P	HV345P	HV348P
	Die in waffle pack	0°C to + 70°C	HV341X	HV343X	HV345X	HV348X

* 300 mil wide SO package
† For Hi-Rel process flows, refer to page 5-3 of the Databook.

Features

- ☐ ±20V to ±50V single and dual supply operation
- ☐ R_{ON} less than 55Ω (HV348)
- ☐ Signal switching from positive to negative rail
- ☐ -50db OFF isolation at 5MHz
- ☐ Withstand +80V to -100 spikes
- ☐ Withstand V_{SIG} with power supply off

Applications

- ☐ Test Equipment and Instruments
- ☐ Diagnostic Systems
- ☐ 48 Volt Telecom Systems
- ☐ Military Electronics

Absolute Maximum Ratings[1]

Supply voltage, V_{PP}		-0.3V to +65V
Supply voltage, V_{NN}		+0.3V to -65V
Data input voltage		V_{NN} to V_{PP}
Input current	Switches	±200mA
	Logic inputs	±30mA
Continuous total power dissipation[2]	Plastic Packages	500mW
	Ceramic Packages	750mW
Storage temperature range		-65°C to +150°C

Notes:
1. All voltages are referenced to V_{SS}.
2. For operation above 25°C ambient, derate linearly to 85°C at 8mW/°C.

General Description

These CMOS/DMOS high voltage analog switches are designed to handle high voltage analog signals. They may be used when analog voltages are low and high voltage immunity is desired. The signal handling capability extends from positive to negative supply voltage; i.e., 100V peak to peak with ±50V power supplies.

Inputs are compatible with CMOS logic, with a zero level turning the switches ON.

Operating supply voltage ranges from ±20V to ±50V with dual output power supplies, with the positive supply current below 300μA and negative supply not exceeding 100μA.

When a single output power supply is used, operating voltage ranges from +20V to +50V, with less than 20μA operating current when logic input signal equals the supply voltage.

With the addition of series diodes on the power supply and ground inputs, the HV341 series drivers will withstand +80V to -100V excursion on the inputs or switch pins without damage, or will withstand signal input with the power supplies OFF.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Typ	Max	Units	Conditions
V_{SIG}	Analog signal range		V_{NN}		V_{PP}	V	
R_{ON}	HV341/343/345	25°C		80	110	Ω	V_{SIG} = ±50V I_{SIG} = 10mA
		Over temp			160		
	HV348	25°C		35	55	Ω	
		Over temp			80		
R_{ON}	ON-Resistance matching			7		%	
V_{IL}	Input low threshold				3.5	V	
V_{IH}	Input high threshold		12			V	
I_{SOL}	Switch OFF leakage	25°C		10	50	nA	V_{SIG} = ±50V
		Over temp		1	5	µA	
I_{PP}	V_{PP} quiescent current			200	600	µA	
I_{NN}	V_{NN} quiescent current			15	200	µA	
I_{IN}	Logic input current			0.1	10	µA	V_{IN} = 0 to 15V
I_{SON}	Switch ON leakage	25°C		10	60	nA	V_{SIG} = ±50V
		Over temp		1	5	µA	

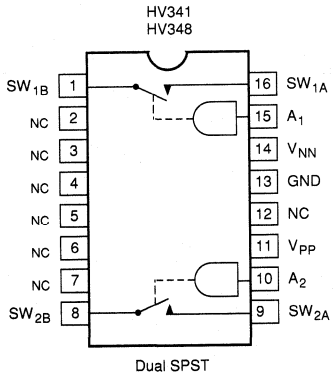
AC Characteristics (@ V_{DD} = 12V, V_{PP} = 60V, T_C = 25°C)

Symbol	Parameter		Min	Typ	Max	Units	Conditions
t_{ON}	Turn-ON time	25°C		0.5	1.0	µs	
		Over temp			1.5		
t_{OFF}	Turn-OFF time	25°C		0.4	0.75	µs	
		Over temp			1.0		
K_O	OFF isolation			-70		dB	25°C, 1MHz
K_{CR}	Switch crosstalk			-75		dB	25°C, 1MHz
$C_{SW(OFF)}$	OFF capacitance across switch			1		pF	T_A = 25°C, V_S = 0V
$C_{SG(OFF)}$	OFF capacitance SW to GND			17		pF	
$C_{SG(ON)}$	ON capacitance SW to GND			38		pF	
Q	Charge injection				100	pC	V_{SIG} = +50V
					240	pC	V_{SIG} = 0V
					480	pC	V_{SIG} = -50V

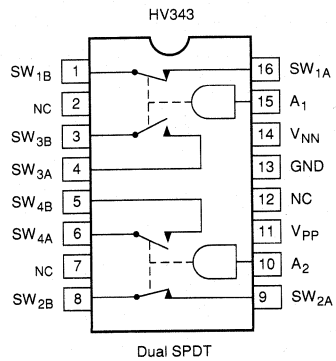
Recommended Operating Conditions

Symbol	Parameter		Min	Typ	Max	Units
V_{NN}	Negative high voltage supply		-50		0	V
V_{PP}	High voltage supply		+20		+50	V
V_{IH}	High-level input voltage		+12		+50	V
V_{IL}	Low-level input voltage		-50		+3.5	V
Operating temperature range		Commercial	0		+70	°C
		Military Hi-Rel (RB)	-55		+125	°C

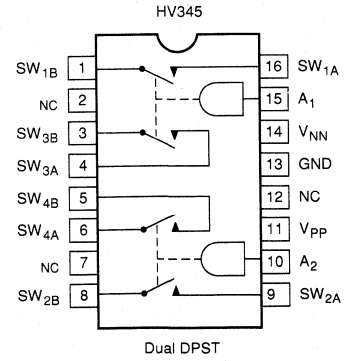
Functional Block Diagrams and Pin Configurations



Dual SPST

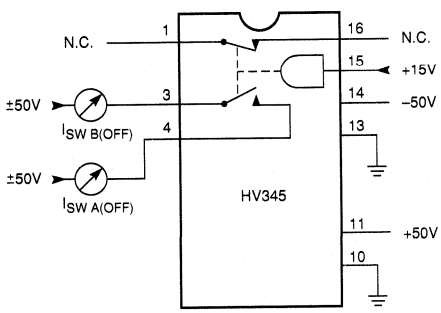


Dual SPDT

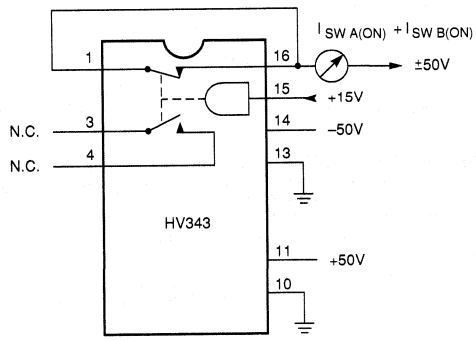


Dual DPST

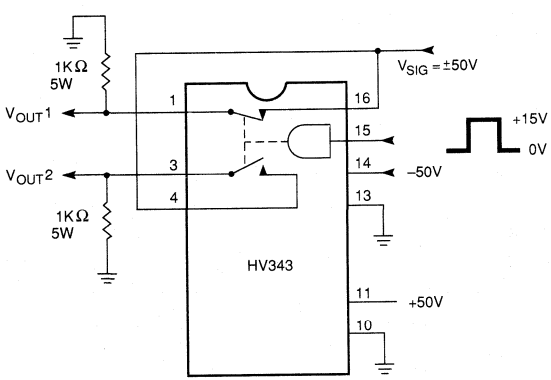
Test Circuits

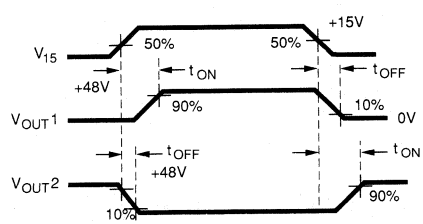


OFF Leakage Test Circuit

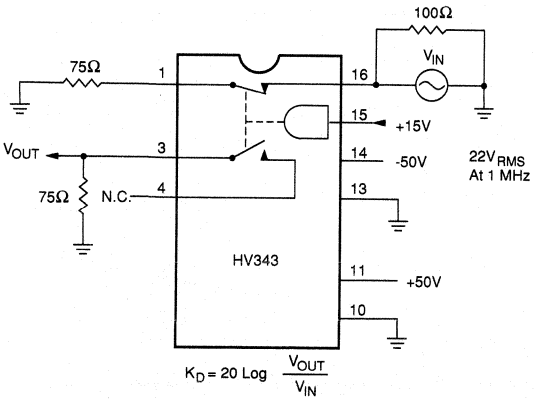


ON Leakage Test Circuit

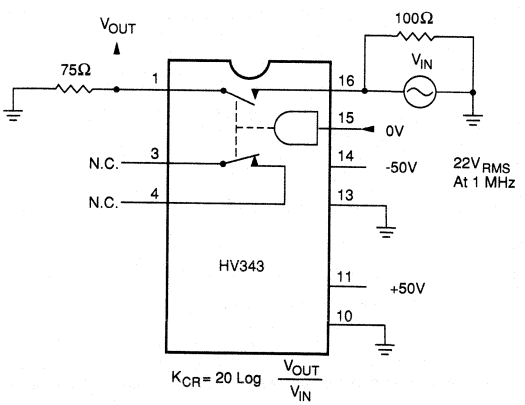




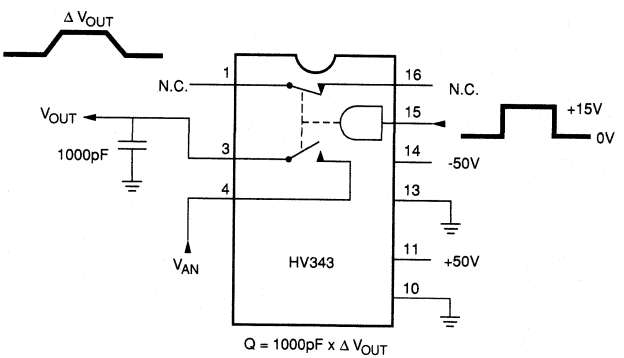
Switching Time Test Circuit



Channel–Channel Crosstalk Circuit



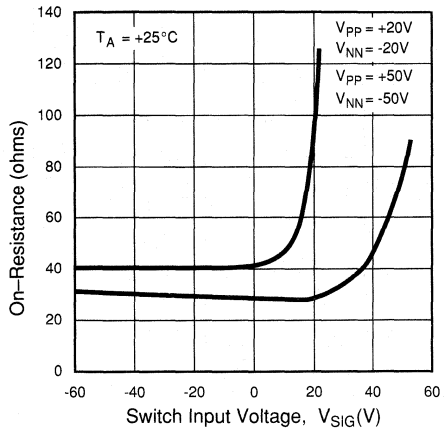
OFF Isolation Test Circuit



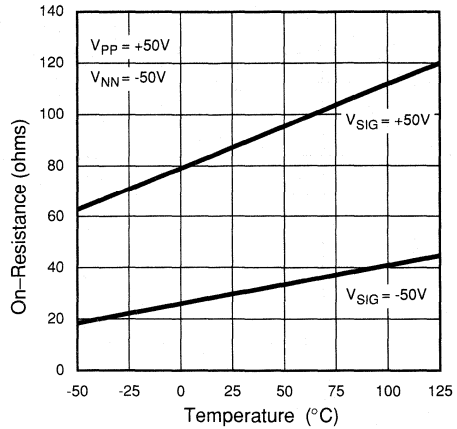
Charge Injection Test Circuit

Typical Operating Characteristics

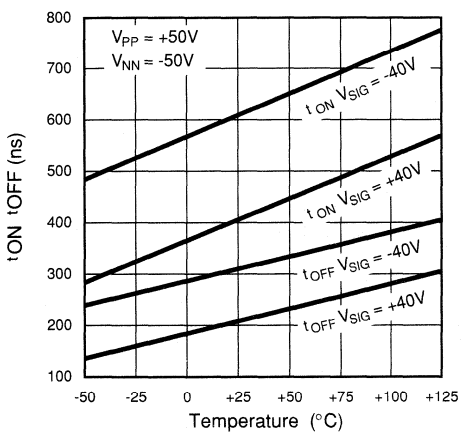
On–Resistance vs. Switch Input Voltage



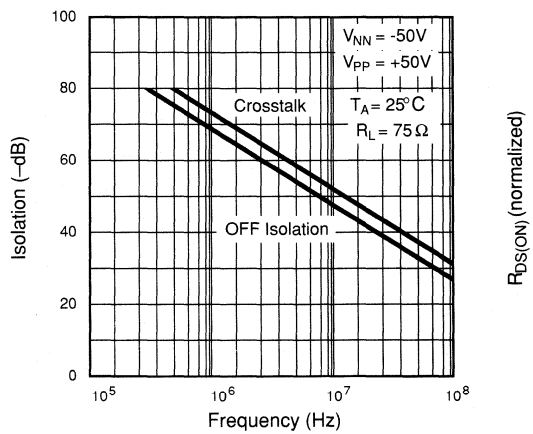
On-Resistance vs. Temperature



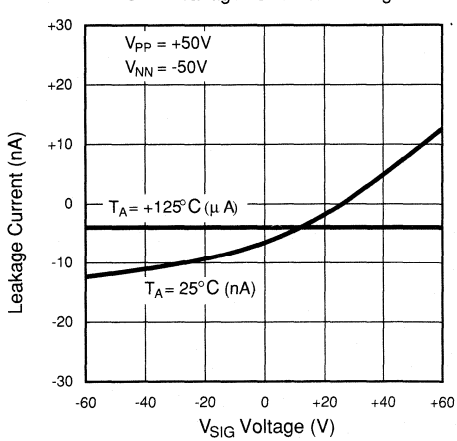
Switching Time vs. Temperature



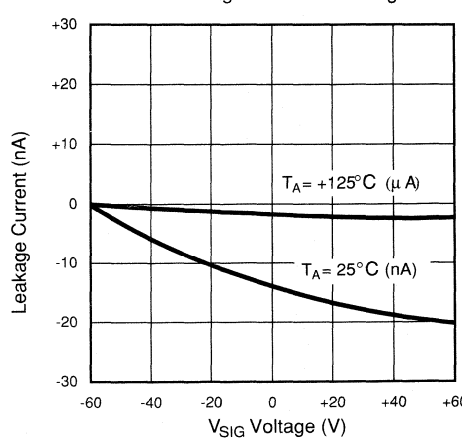
OFF Isolation And Crosstalk vs. Frequency



OFF Leakage vs. Switch Voltage



ON Leakage vs. Switch Voltage



Applications Information

Analog Signal Range

The HV341 family's analog signal range is equal to the power supply value, up to ±50V with split power supplies and +60V with a single power supply (V_{NN} connected to GND). An ON switch is also capable of passing up to 0.5A on a peak current basis. Maximum continuous current is limited only by the package power dissipation (see Absolute Maximum Ratings).

ON Resistance

The ON resistance of the MAX341 series switches is typically 40Ω. R_{ON} does, however, increase as the switch voltage (VSIG) approaches V_{PP}. For example, with ±50V supplies and a +50V analog signal, R_{ON} will be typically less than 100Ω (50Ω for the HV348), and 45Ω (25Ω for the HV348 for -50V signals. With ±50V power supplies , and ±40V switch voltages, R_{ON} is about 40Ω for the +40V case and 30Ω for the -40V case. ON resistance can be reduced and current handling capacity can be increased by connecting switches in parallel. This is especially useful in power switching applications. Table 1 and the graph in the Typical Characteristics section further describe the relation between R_{ON} and V_{PP}.

Power Supply Current

The maximum supply current for V_{PP} and V_{NN} at 25°C is 300µA and 100µA, respectively. However, the positive supply current (1+) is partly dependent on the input logic level and can be reduced if control signals of a larger amplitude than 0V and 15V are used. If the control inputs swing to within 4V of V_{PP} and V_{NN} then 1+ drops to a typical value of 200µA.

Control Inputs

15V logic level inputs are required to turn switches on or off, but the control inputs can also accept levels up to V_{PP} and V_{NN}. An input greater than 12V constitutes a "1" state (switch OFF), and an input less than 3.5V will constitute a "0" state (switch ON).

Standard TTL logic can be used with HV341 series switches if a level shifter such as the MC14504 is used to drive the control inputs as shown in Figure 1. Open collector drivers, with external pull-up resistors, can be used in a similar fashion as well.

Table 1: ON Resistance

V_{PP}/V_{NN}	R_{ON} at $V_{SIG} = V_{PP}$	R_{ON} at $V_{SIG} = V_{NN}$
+20V/-20V	127Ω	39Ω
+30V/-30V	105Ω	36Ω
+40V/-40V	92Ω	32Ω
+50V/-50V	84Ω	30Ω
+40V/GND	127Ω	39Ω
+60V/GND	105Ω	36Ω

Note: Typical R_{ON} for the HV348 is approximately one half of the above values.

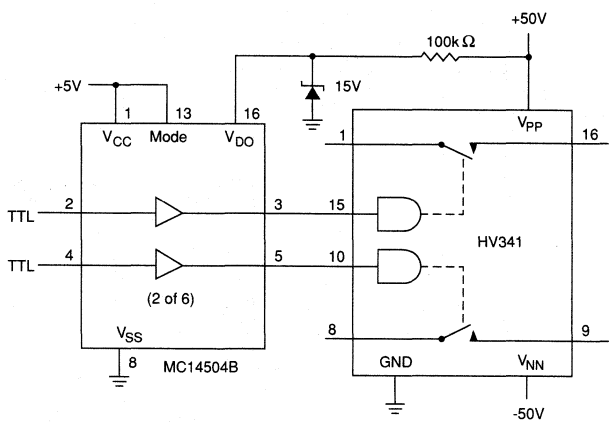


Figure 1. Using TTL Control Levels

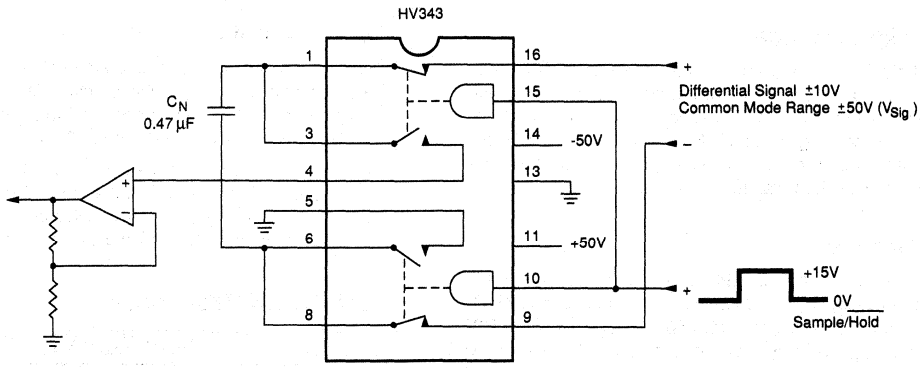


Figure 2. Flying Capacitor Differential to Single-Ended Converter With ±50V Common-Mode Range.

Flying Capacitor Input

A "flying capacitor" differential to single-ended converter takes advantage of the HV343's wide input voltage range, which allows large common mode inputs to be rejected. As shown in figure 2, a capacitor is alternately charged by the differential input signal and then is connected to an op-amp or A-to-D input. An instrumentation amplifier is not required since the output signal can be referenced to ground. Sample-hold operation is also built into the design and the HV343's break-before-make operation ensures that the output sees only the differential portion of the input signal. A similar approach can also be used for single-ended to differential signal conversion as well.

Parallel Switches

In designs where power switching ability is needed, any of the HV 341 series switches can be connected in parallel to increase current handling capability and reduce ON resistance. Applications such as ultrasonics, RF power, and DC motor drive are areas where this is often important. An HV348 is shown in a parallel configuration in Figure 3. The resulting SPST switch has a typical R_{ON} of 12Ω (5Ω for signals more than 10V below V_{PP}) and can handle pulsed loads of up to 0.5 Amps. With ±50V power supplies, the peak-to-peak signal range is still 100V, and 10MHz signals can be switched while maintaining typically -50dB of isolation.

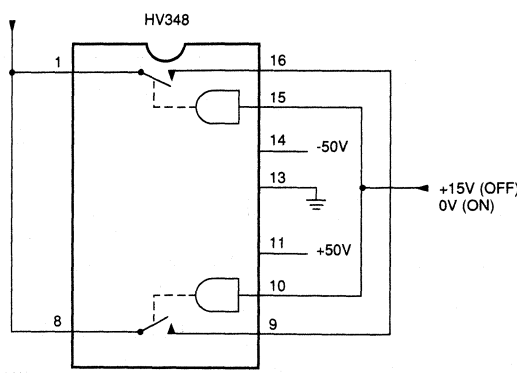


Figure 3. Minimum R_{ON} (5 to 10Ω typ.) High Voltage Switch.

32-Channel Serial To Parallel Converter With P-Channel Open Drain Outputs

Ordering Information

Device	Package Options			
	44 J-Lead Quad Ceramic Chip Carrier	44 J-Lead Quad Plastic Chip Carrier	Die	44 J-Lead Quad Ceramic Chip Carrier (MIL-STD-883 Processed*)
HV41	HV4122DJ	HV4122PJ	HV4122X	RBHV4122DJ
HV42	HV4222DJ	HV4222PJ	HV4222X	RBHV4222DJ

* For Hi-Rel process flows, please refer to page 5-3 in the Databook

Features

- ☐ Processed with HVCMOS® technology
- ☐ Output voltages to -225V
- ☐ Source current minimum 80mA
- ☐ Shift register speed 8MHz
- ☐ Strobe and enable inputs
- ☐ CMOS compatible inputs
- ☐ Forward and reverse shifting options
- ☐ 44-lead plastic and ceramic surface mount packages
- ☐ Hi-Rel processing available
- ☐ Can be used with the HV51 and HV52 to provide 200V push-pull operation

Absolute Maximum Ratings

Supply voltage, V_{DD}[1]		+0.5V to -15.5V
Off state output voltage[1]		+0.5V to -250V
Logic input levels[1]		+0.5V to V_{DD} - 0.5V
Ground current[2]		1.5A
Continuous total power dissipation[4]	Ceramic	1500mW
	Plastic	1200mW
Operating temperature range	Ceramic	-40°C to +85°C
	Plastic	0°C to +70°C
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. All voltages are referenced to V_{SS}.
2. Duty cycle is limited by the total power dissipated in the package.
3. For operation above 25°C ambient, derate linearly to 85°C at 15mW/°C.

General Description

The HV41 and HV42 are low voltage serial to high voltage parallel converters wtih P-Channel open drain outputs.These devices have been designed for use as drivers for AC electroluminescent displays. They can also be used in any application requiring multiple output high voltage current source capabilities such as driving inkjet and electrostatic print heads, plasma panels, or vacuum fluorescent displays.

These devices consist of a 32-bit shift register and control logic to perform the Output Enable and All-ON functions. Data is shifted through the shift register on the logic high to low transition of the clock. The HV41 shifts in the counterclockwise direction when viewed from the top of the package and the HV42 shifts in the clockwise direction. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register. Operation of the shift register is not affected by the OE (Output Enable) or the STR (Strobe) inputs.

For applications requiring active pull down as well as pull up, the HV41 and HV42 can be paired with the HV52 and HV51 devices, respectively.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics (voltages referenced to V_{SS})

Symbol	Parameter		Min	Max	Units	Conditions
I_{DD}	V_{DD} supply current			-15	mA	f_{CLK} = 8 MHz F_{DATA} = 4 MHz
I_{DDQ}	Quiescent V_{DD} supply current			-100	µA	ALL V_{IN} = 0V
$I_{O(OFF)}$	Off state output current			-100	µA	All SWS parallel
I_{IH}	High-level logic input current			-1	µA	V_{IH} = -12V
I_{IL}	Low-level logic input current			+1	µA	V_{IL} = 0V
V_{OH}	High-level output data out		V_{DD} + 1.0V		V	I_{Dout} = -100µA
V_{OL}	Low-level output voltage	HV_{OUT}		-30.0	V	I_{HVout} = -80mA
		Data out		-1.0	V	I_{Dout} = -100µA
V_{OC}	HV_{OUT} clamp voltage			+1.5	V	I_{OL} = +80mA

AC Characteristics (@ V_{DD} = -12V, V_{SS} = 0V)

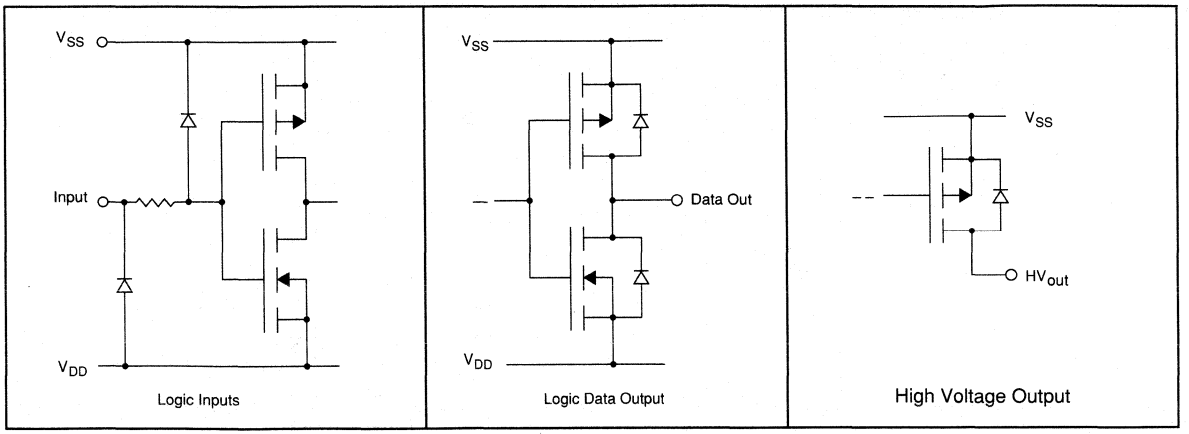
Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock frequency		8	MHz	
t_{WH}/t_{WL}	Clock width high or low	62		ns	
t_{SU}	Data set-up time before clock rises	50		ns	
t_H	Data hold time after clock rises	20		ns	
t_{ON}	Turn ON time, HV_{OUT} from enable		400	ns	R_L = 10K to -225V
t_{DHL}	Delay time clock to data high to low		100	ns	
t_{DLH}	Delay time clock to data low to high		100	ns	

Recommended Operating Conditions

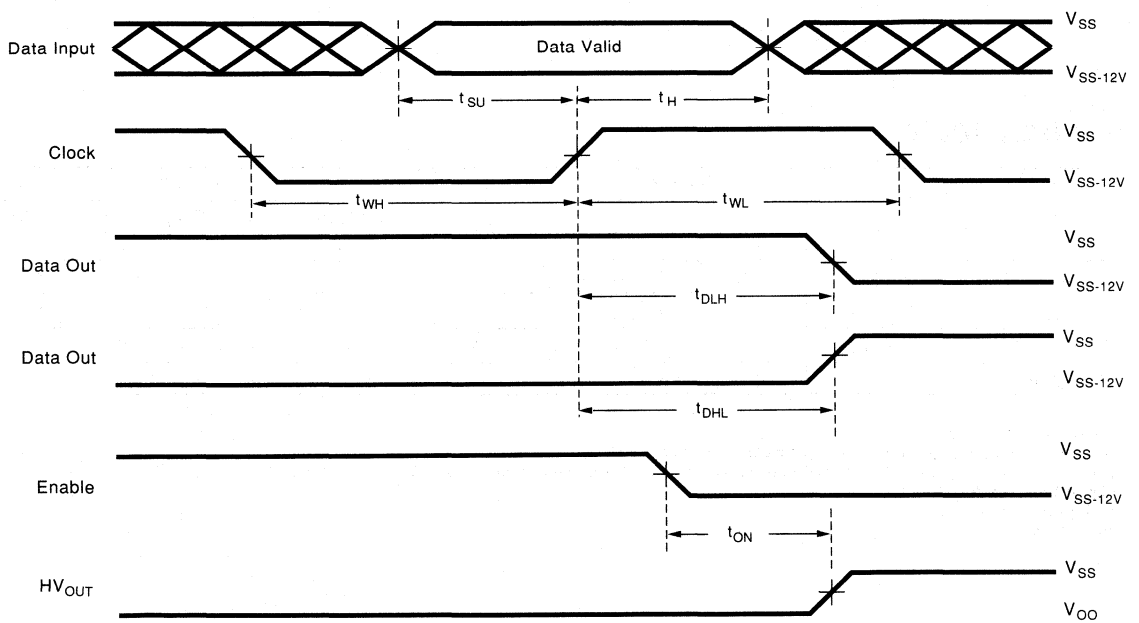
Symbol	Parameter		Min	Nom	Max	Units
V_{DD}	Logic supply voltage		-10.8	-12	-13.2	V
V_{OO}	Output off voltage		+0.3		-225	V
V_{IH}	High-level input voltage (LOGIC "1")		V_{DD} + 2V		V_{DD}	V
V_{IL}	Low-level input voltage (LOGIC "0")		0		-2.0	V
f_{CLK}	Clock frequency				8	MHz
T_A	Operating free-air temperature	Commercial	-40		+85	°C
		Military Hi-Rel (RB)	-55		+125	°C

Note : All voltages are referenced to V_{SS}.

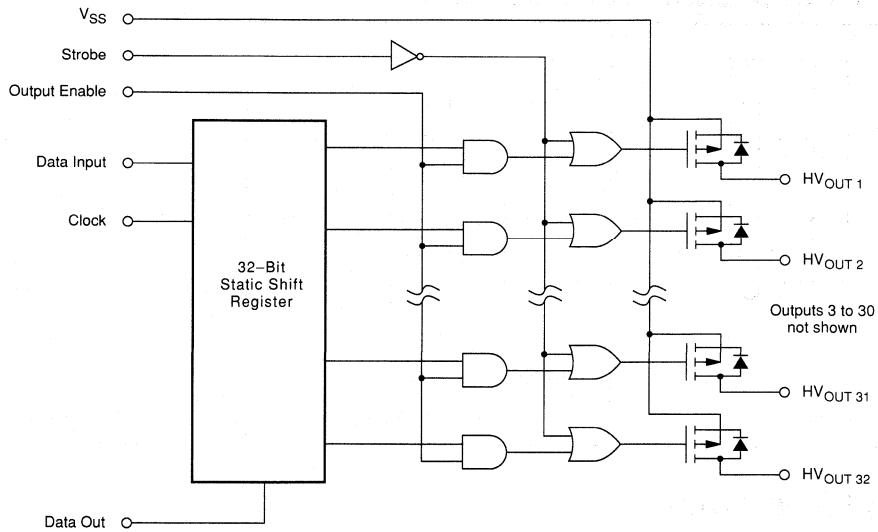
Input and Output Equivalent Circuits



Switching Waveforms



Functional Block Diagram



Function Table

Function	Inputs				Outputs		
	DI	CLK	OE	STR	Shift Reg 1 2...32	HV Outputs 1 2...32	Data Out *
All on	X	X	X	L	* *...*	All On	*
All off	X	X	L	H	* *...*	All Off	*
Load S/R	H or L	↓	L	H	H or L *...*	On or Off *...*	
Output enable	X	H or L	H	H	* *...*	On or Off *...*	*

Notes:
X = Not relevant to the output state.
* = Dependent on previous stage's state before the last CLK : High to low transition.
A logic high bit in the shift register will turn on the corresponding output when the strobe and output enable inputs are both high.
↓ = High-to-low transition, -12V to V_{SS}
H = High level = -12V
L = Low level = 0V

Pin Configurations

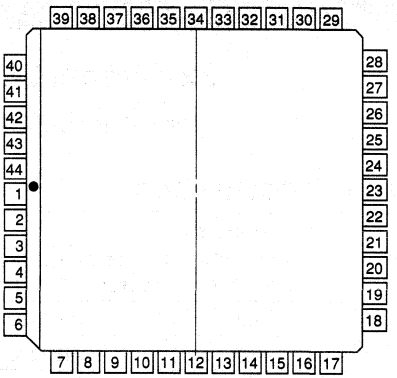
HV41
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 17	23	Output Enable
2	HV_{OUT} 18	24	Clock
3	HV_{OUT} 19	25	V_{SS}
4	HV_{OUT} 20	26	V_{DD}
5	HV_{OUT} 21	27	Strobe
6	HV_{OUT} 22	28	Data In
7	HV_{OUT} 23	29	HV_{OUT} 1
8	HV_{OUT} 24	30	HV_{OUT} 2
9	HV_{OUT} 25	31	HV_{OUT} 3
10	HV_{OUT} 26	32	HV_{OUT} 4
11	HV_{OUT} 27	33	HV_{OUT} 5
12	HV_{OUT} 28	34	HV_{OUT} 6
13	HV_{OUT} 29	35	HV_{OUT} 7
14	HV_{OUT} 30	36	HV_{OUT} 8
15	HV_{OUT} 31	37	HV_{OUT} 9
16	HV_{OUT} 32	38	HV_{OUT} 10
17	N/C	39	HV_{OUT} 11
18	Data Out	40	HV_{OUT} 12
19	N/C	41	HV_{OUT} 13
20	N/C	42	HV_{OUT} 14
21	N/C	43	HV_{OUT} 15
22	N/C	44	HV_{OUT} 16

HV42
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 16	23	Output Enable
2	HV_{OUT} 15	24	Clock
3	HV_{OUT} 14	25	V_{SS}
4	HV_{OUT} 13	26	V_{DD}
5	HV_{OUT} 12	27	Strobe
6	HV_{OUT} 11	28	Data In
7	HV_{OUT} 10	29	HVout 32
8	HV_{OUT} 9	30	HV_{OUT} 31
9	HV_{OUT} 8	31	HV_{OUT} 30
10	HV_{OUT} 7	32	HV_{OUT} 29
11	HV_{OUT} 6	33	HV_{OUT} 28
12	HV_{OUT} 5	34	HV_{OUT} 27
13	HV_{OUT} 4	35	HV_{OUT} 26
14	HV_{OUT} 3	36	HV_{OUT} 25
15	HV_{OUT} 2	37	HV_{OUT} 24
16	HV_{OUT} 1	38	HV_{OUT} 23
17	N/C	39	HV_{OUT} 22
18	Data Out	40	HV_{OUT} 21
19	N/C	41	HV_{OUT} 20
20	N/C	42	HV_{OUT} 19
21	N/C	43	HV_{OUT} 18
22	N/C	44	HV_{OUT} 17

Package Outline



top view

44-pin J-lead Package

32-Channel Serial To Parallel Converter with P-Channel Open Drain Outputs

Ordering Information

Device	Recommended Operating V_{PP} Max	Package Options			
		44 J-Lead Quad Ceramic Chip Carrier	44 J-Lead Quad Plastic Chip Carrier	44 Quad Plastic Gullwing	Die
HV45	-300	HV4530DJ	HV4530PJ	HV4530PG	HV4530X
	-220	HV4522DJ	HV4522PJ	HV4522PG	HV4522X
HV46	-300	HV4630DJ	HV4630PJ	HV4630PG	HV4630X
	-220	HV4622DJ	HV4622PJ	HV4622PG	HV4622X

Features

- ☐ Processed with HVCMOS Technology
- ☐ Output voltages to -300V
- ☐ Source current minimum 60 mA
- ☐ Shift register speed 8 MHz
- ☐ Polarity and blanking inputs
- ☐ CMOS compatible inputs
- ☐ Forward and reverse shifting options
- ☐ 44-lead plastic and ceramic surface mount packages
- ☐ Hi-Rel processing available
- ☐ Can be used with the HV55 and HV56 to provide 300V push pull operation

Absolute Maximum Ratings

Supply voltage, V_{DD}[1]		+0.5V to -16V
Off state output voltage	HV4530/HV4630	+0.5V to -315V
	HV4522/ HV4622	+0.5V to -220V
Logic input levels[1]		+0.5V to V_{DD} - 0.3V
Ground currrent[2]		1.5A
Continuous total power dissipation[4]	Ceramic	1500mW
	Plastic	1200mW
Operating temperature range	Ceramic	-40°C to +85°C
	Plastic	0°C to +70°C
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. All voltages are referenced to V_{SS}.
2. Duty cycle is limited by the total power dissipated in the package.
3. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

General Description

The HV45 and HV46 are low-voltage serial to high-voltage parallel converters with P-Channel open drain outputs. These devices have been designed for use as drivers for AC-electroluminescent displays. They can also be used in any application requiring multiple output high-voltage current source capabilities such as driving inkjet and electrostatic print heads, plasma panels, or vacuum fluorescent displays.

These devices consist of a 32-bit shift register, 32 data latches, and control logic to perform polarity and blanking functions. Data is shifted through the shift register on the logic high-to-low transition of the clock. The HV45 shifts in the counterclockwise direction when viewed from the top of the package and the HV46 shifts in the clockwise direction. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register. The data in the shift register is latched when the latch enable pin is brought to logic high and then returned to ground. If the latch enable pin is held high, the latch becomes transparent and the shift register data is directly reflected in the outputs.

For applications requiring active pull down as well as pull up, the HV45 and HV46 can be paired with the HV55 and HV56 devices, respectively.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Max	Units	Conditions
I_{DD}	V_{DD} supply current			-15	mA	f_{CLK} = 8 MHz F_{DATA} = 4 MHz
I_{DDQ}	Quiescent V_{DD} supply current			-100	µA	$V_{IN} = V_{SS}$ or V_{DD}
$I_{O(OFF)}$	Off state output current			-100	µA	All SWS parallel
I_{IH}	High-level logic input current			-1	µA	$V_{IH} = V_{DD}$
I_{IL}	Low-level logic input current			+1	µA	$V_{IL} = V_{SS}$
V_{OH}	High-level output data out		V_{DD} + 1.0V		V	I_{Dout} = -100µA
V_{OL}	Low-level output voltage	HV_{OUT}		-30.0	V	I_{HVout} = -60mA
		Data out		-1.0	V	I_{Dout} = -100µA
V_{OC}	HV_{OUT} clamp voltage			+1.5	V	I_{OL} = +60mA

AC Characteristics (V_{DD} = 12V, T_C = 25°C)

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock frequency		8	MHz	
t_{WH}/t_{WL}	Clock width high or low	62		ns	
t_{SU}	Data set-up time before clock rises	50		ns	
t_H	Data hold time after clock rises	20		ns	
t_{ON}	Turn ON time, HV_{OUT} from enable		400	ns	R_L = 10K to V_{OO} MAX
t_{DHL}	Delay time clock to data high to low		100	ns	C_L = 15pF
t_{DLH}	Delay time clock to data low to high		100	ns	C_L = 15pF
t_{DLE}	Delay time clock to $\overline{LE}$ low to high	50		ns	
t_{WLE}	Width of $\overline{LE}$ pulse	50		ns	
t_{SLE}	LE set-up time before clock falls	50		ns	

Recommended Operating Conditions

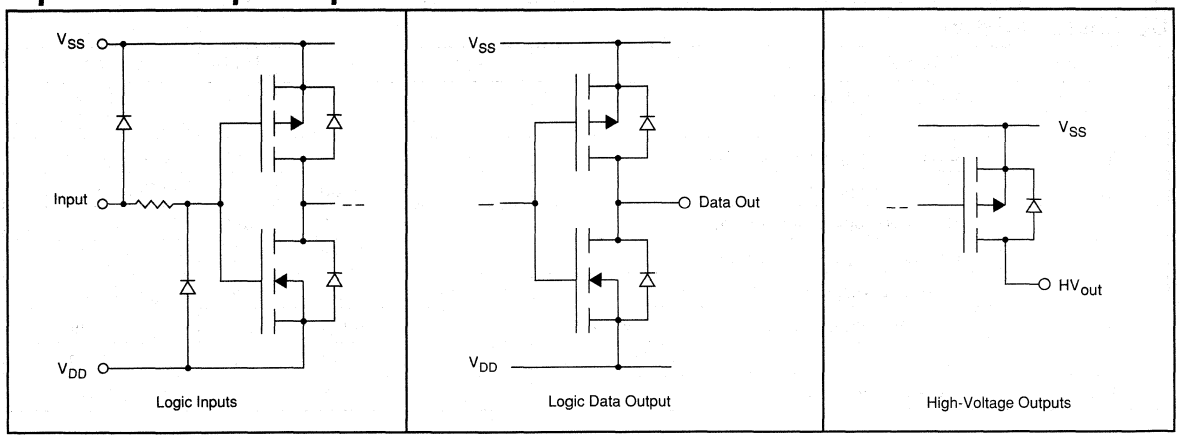
(Note 1)

11

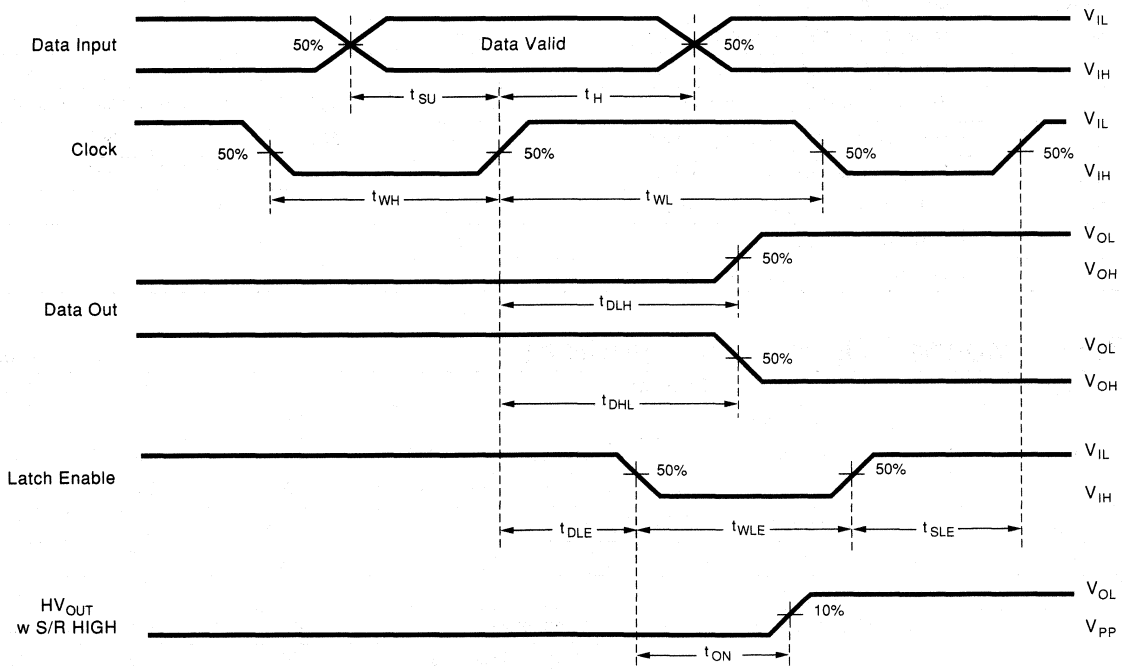
Symbol	Parameter		Min	Max	Units
V_{DD}	Logic supply voltage		-10.8	-13.2	V
V_{OO}	Output off voltage	HV4530 and HV4630	+0.3	-300	V
		HV4522 and HV4622	+0.3	-200	V
V_{IH}	High-level input voltage (LOGIC "1")		V_{DD} + 2V	V_{DD}	V
V_{IL}	Low-level input voltage (LOGIC "0")		0	-2.0	V
f_{CLK}	Clock frequency			8	MHz
T_A	Operating free-air temperature	Commercial	-40	+85	°C
		Military Hi-Rel (RB)	-55	+125	°C

Note 1: All voltages are referenced to V_{SS}.

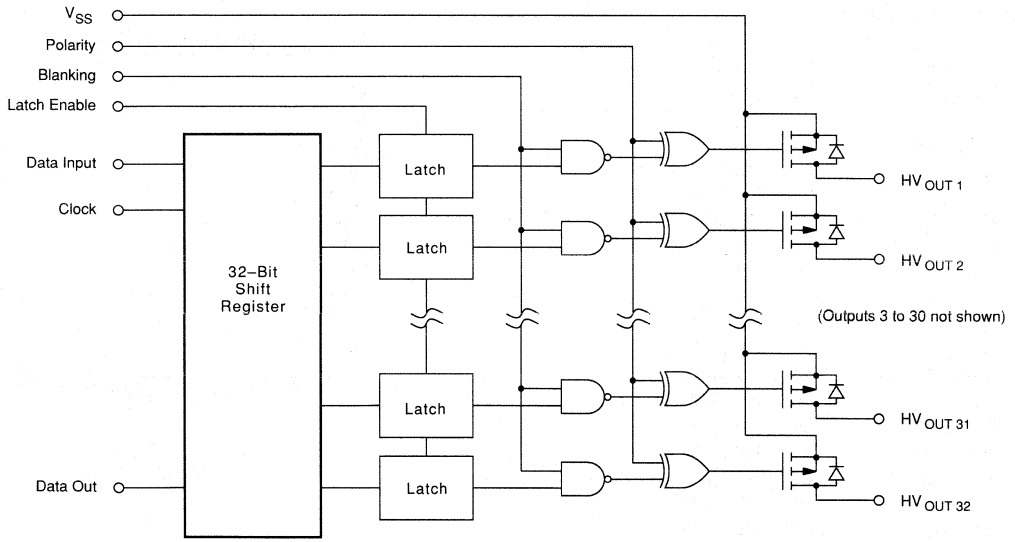
Input and Output Equivalent Circuits



Switching Waveforms



Functional Block Diagram



Function Table

Function	Inputs					Outputs		
	Data	CLK	$\overline{LE}$	$\overline{BL}$	$\overline{POL}$	Shift Reg 1 2...32	HV Outputs 1 2...32	Data Out *
All on	X	X	X	L	L	* *...*	H H...H	*
All off	X	X	X	L	H	* *...*	L L...L	*
Invert mode	X	X	L	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Load S/R	H or L	↓	L	H	H	H or L *...*	* *...*	*
Load latches	X	H or L	↑	H	H	* *...*	* *...*	*
	X	H or L	↑	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Transparent latch mode	L	↓	H	H	H	L *...*	L *...*	*
	H	↓	H	H	H	H *...*	H *...*	*

Notes:
H = high level, L = low level, X = irrelevant, Ø = low-to-high transition, -12V to V_{SS}.
* = dependent on previous stage's state before the last CLK Ø or last LE high.

Pin Configurations

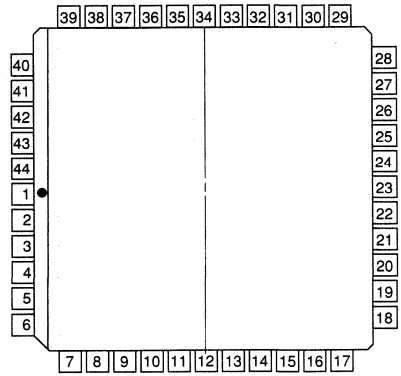
HV45
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 17	23	Clock
2	HV_{OUT} 18	24	V_{SS}
3	HV_{OUT} 19	25	V_{DD}
4	HV_{OUT} 20	26	Latch Enable
5	HV_{OUT} 21	27	Data In
6	HV_{OUT} 22	28	Blanking
7	HV_{OUT} 23	29	HV_{OUT} 1
8	HV_{OUT} 24	30	HV_{OUT} 2
9	HV_{OUT} 25	31	HV_{OUT} 3
10	HV_{OUT} 26	32	HV_{OUT} 4
11	HV_{OUT} 27	33	HV_{OUT} 5
12	HV_{OUT} 28	34	HV_{OUT} 6
13	HV_{OUT} 29	35	HV_{OUT} 7
14	HV_{OUT} 30	36	HV_{OUT} 8
15	HV_{OUT} 31	37	HV_{OUT} 9
16	HV_{OUT} 32	38	HV_{OUT} 10
17	N/C	39	HV_{OUT} 11
18	Data Out	40	HV_{OUT} 12
19	N/C	41	HV_{OUT} 13
20	N/C	42	HV_{OUT} 14
21	N/C	43	HV_{OUT} 15
22	Polarity	44	HV_{OUT} 16

HV46
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 16	23	Clock
2	HV_{OUT} 15	24	V_{SS}
3	HV_{OUT} 14	25	V_{DD}
4	HV_{OUT} 13	26	Latch Enable
5	HV_{OUT} 12	27	Data In
6	HV_{OUT} 11	28	Blanking
7	HV_{OUT} 10	29	HVout 32
8	HV_{OUT} 9	30	HV_{OUT} 31
9	HV_{OUT} 8	31	HV_{OUT} 30
10	HV_{OUT} 7	32	HV_{OUT} 29
11	HV_{OUT} 6	33	HV_{OUT} 28
12	HV_{OUT} 5	34	HV_{OUT} 27
13	HV_{OUT} 4	35	HV_{OUT} 26
14	HV_{OUT} 3	36	HV_{OUT} 25
15	HV_{OUT} 2	37	HV_{OUT} 24
16	HV_{OUT} 1	38	HV_{OUT} 23
17	N/C	39	HV_{OUT} 22
18	Data Out	40	HV_{OUT} 21
19	N/C	41	HV_{OUT} 20
20	N/C	42	HV_{OUT} 19
21	N/C	43	HV_{OUT} 18
22	Polarity	44	HV_{OUT} 17

Package Outline



top view

44-pin J-lead Package

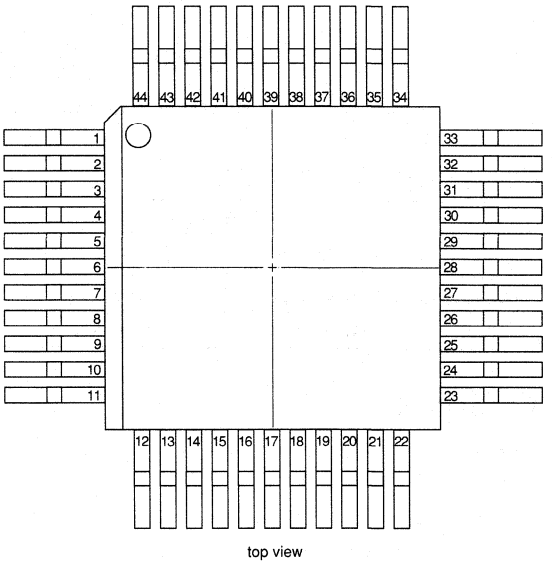
Pin Configurations

HV45

44-Pin Plastic Gullwing (QFP) Package

Pin	Function	Pin	Function
1	HV_{OUT} 12	23	Data Out
2	HV_{OUT} 13	24	N/C
3	HV_{OUT} 14	25	N/C
4	HV_{OUT} 15	26	N/C
5	HV_{OUT} 16	27	Polarity
6	HV_{OUT} 17	28	Clock
7	HV_{OUT} 18	29	V_{SS}
8	HV_{OUT} 19	30	V_{DD}
9	HV_{OUT} 20	31	Latch Enable
10	HV_{OUT} 21	32	Data In
11	HV_{OUT} 22	33	Blanking
12	HV_{OUT} 23	34	HV_{OUT} 1
13	HV_{OUT} 24	35	HV_{OUT} 2
14	HV_{OUT} 25	36	HV_{OUT} 3
15	HV_{OUT} 26	37	HV_{OUT} 4
16	HV_{OUT} 27	38	HV_{OUT} 5
17	HV_{OUT} 28	39	HV_{OUT} 6
18	HV_{OUT} 29	40	HV_{OUT} 7
19	HV_{OUT} 30	41	HV_{OUT} 8
20	HV_{OUT} 31	42	HV_{OUT} 9
21	HV_{OUT} 32	43	HV_{OUT} 10
22	N/C	44	HV_{OUT} 11

Package Outline



top view

44-pin PQFP Package

HV46

44-Pin Plastic Gullwing (QFP) Package

Pin	Function	Pin	Function
1	HV_{OUT} 21	23	Data Out
2	HV_{OUT} 20	24	N/C
3	HV_{OUT} 19	25	N/C
4	HV_{OUT} 18	26	N/C
5	HV_{OUT} 17	27	Polarity
6	HV_{OUT} 16	28	Clock
7	HV_{OUT} 15	29	V_{SS}
8	HV_{OUT} 14	30	V_{DD}
9	HV_{OUT} 13	31	Latch Enable
10	HV_{OUT} 12	32	Data In
11	HV_{OUT} 11	33	Blanking
12	HV_{OUT} 10	34	HV_{OUT} 32
13	HV_{OUT} 9	35	HV_{OUT} 31
14	HV_{OUT} 8	36	HV_{OUT} 30
15	HV_{OUT} 7	37	HV_{OUT} 29
16	HV_{OUT} 6	38	HV_{OUT} 28
17	HV_{OUT} 5	39	HV_{OUT} 27
18	HV_{OUT} 4	40	HV_{OUT} 26
19	HV_{OUT} 3	41	HV_{OUT} 25
20	HV_{OUT} 2	42	HV_{OUT} 24
21	HV_{OUT} 1	43	HV_{OUT} 23
22	N/C	44	HV_{OUT} 22

64-Channel Serial To Parallel Converter With P-Channel Open Drain Outputs

Ordering Information

Device	Package Options	
	80-Lead Quad Plastic Gullwing	Die
HV49	HV4937PG	HV4937X

Features

- HVCMOS® Technology
- Output voltages up to -375V
- Source current minimum 1 mA
- Shift register speed 6 MHz
- Latched outputs
- CMOS compatible inputs
- Forward and reverse shifting options

Absolute Maximum Ratings[1]

Supply voltage, V_{DD}	+0.5V to -9V
Supply voltage, V_{PP}	+0.5V to -375V
Logic input levels	+0.5V to V_{DD} -0.5V
Ground current	0.75A
Continuous total power dissipation[2]	1200mW
Operating temperature range	0°C to +85°C
Storage temperature range	-65°C to +150°C

Notes:
1. All voltages are referenced to GND.
2. For operation above 25°C ambient derate linearly by 15mW/°C up to 85°C.

General Description

The HV49 is a low voltage serial to high voltage parallel converter with open drain outputs. It has been designed especially for use as a driver for electrostatic printers.

This device consists of a 64-bit shift register, 64 latches, latch enable (LE), and output enable (OE). Data is shifted through the shift register on the high to low transition of the clock. When the DIR pin is set high, the HV49 shifts in the counterclockwise direction when viewed from the top of the package. When the DIR pin is set low, the HV49 shifts in the clockwise direction. A serial data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register. Operation of the shift register is not affected by the LE or the OE inputs. Transfer of data from the shift register to the latch occurs when the LE input is high. The data in the latch is stored when LE is low.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Typ	Max	Units	Conditions
I_{DD}	V_{DD} Supply Current				-15	mA	f_{CLK} = 6MHz, f_{DATA} = 3MHz $\overline{LE}$ = LOW
I_{DDQ}	Quiescent V_{DD} Supply Current				-250	µA	All V_{IN} = 0V
$I_{O(OFF)}$	Off State Output Current at 25°C, per Switch				-100	nA	Output high, and at 375V
I_{IH}	High-Level Logic Input Current				-10	µA	$V_{IH} = V_{DD}$
I_{IL}	Low-Level Logic Input Current				+10	µA	V_I = 0V
V_{OH}	High-Level Data Out				V_{DD} +1	V	ID_{OUT} = -100µA
V_{OL}	Low-Level Output	HV_{OUT}	-10			V	IHV_{OUT} = -1mA
		Data Out	-1			V	ID_{OUT} = -100µA
V_{OC}	HV_{OUT} Clamp Voltage				-3.0	V	I_{OL} = -1mA
C_{HVO}	Output Capacitance per Channel				3	pF	V_{DS} = 100V

AC Characteristics

Symbol	Parameter	Min	Typ	Max	Units	Conditions
f_{CLK}	Clock Frequency			6	MHz	
t_W	Clock Width High or Low	83			ns	
t_{SU}	Data Setup Time Before Clock Falls	35			ns	
t_H	Data Hold Time After Clock Falls	15			ns	
t_{WLE}	Width of Latch Enable Pulse	83			ns	
t_{DLE}	$\overline{LE}$ Delay Time After Falling Edge of Clock	35			ns	
t_{SLE}	$\overline{LE}$ Setup Time Before Falling Edge of Clock	40			ns	
t_{DHL}	Clock Delay Time Data High to Low			135	ns	
t_{DLH}	Clock Delay Time Data Low to High			135	ns	

Recommended Operating Conditions

Symbol	Parameter	Min	Typ	Max	Units
V_{DD}	Logic supply voltage	-4.5	-5	-5.5	V
V_{PP}	High voltage supply	+8.0		-375	V
V_{IH}	High-level input voltage	V_{DD} +3.5		V_{DD}	V
V_{IL}	Low-level input voltage	0		-0.8	V
T_A	Operating free-air temperature	0		+85	°C

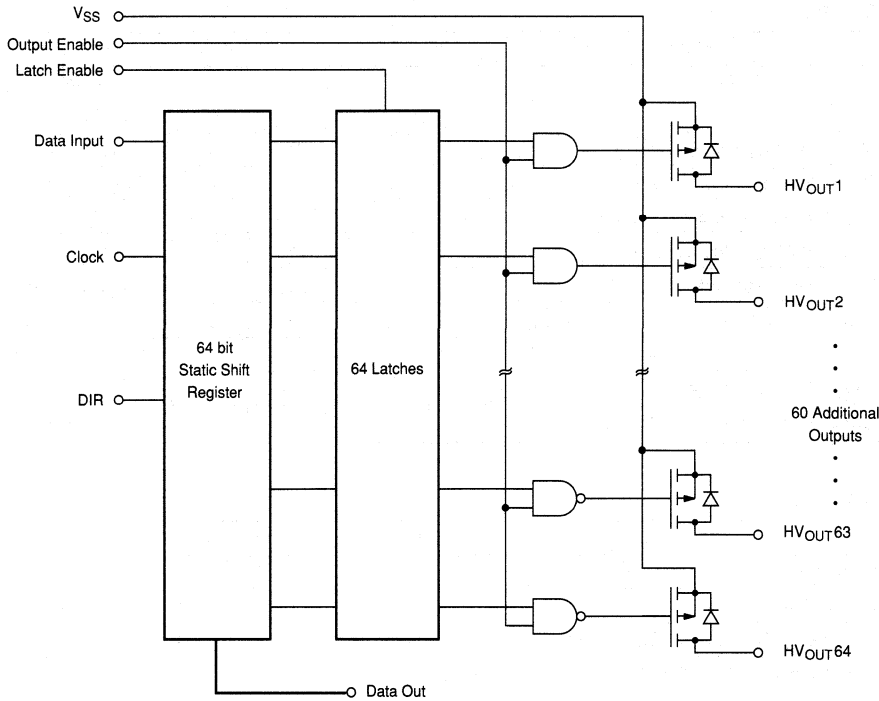
Note:

Power-up sequence should be the following:

1. Connect ground.
2. Apply VDD.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply VPP.

Power-down sequence should be the reverse of the above.

Functional Block Diagram



Function Table

Function	Inputs						Outputs		
	Data	CLK	LE	OE	DIR	Shift Reg 1 2 ... 64	Latch 1 2 ... 64	HV_{OUT} 1 2 ... 64	D_{OUT}
All off	X	X	X	L	X	*...*	*...*	H...H	*
Load S/R	H or L	↓	L	L	H	H or L...Qn → Qn+1	*...*	H...H	*
	H or L	↓	L	L	L	H or L...Qn → Qn-1	*...*	H...H	*
Load Latch	H or L	↓	H	L	X	H or L...*	H or L...*	H...H	*
Output Enable Transparent Latch Mode	X	H or L	H	H	X	H or L...*	H or L...*	L or H...*	*
	H	↓	H	H	X	H...*	H...*	L ...*	*
	L	↓	H	H	X	L ...*	L...*	H...*	*

Notes:

X = Don't care

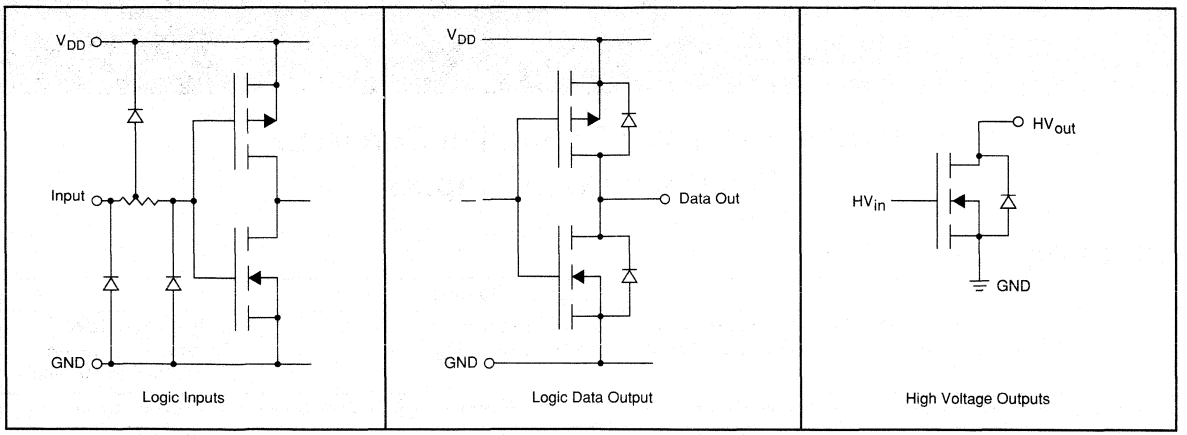
* = Dependent on previous stage's state before the last CLK : High to low transition.

↓ = High to low transition

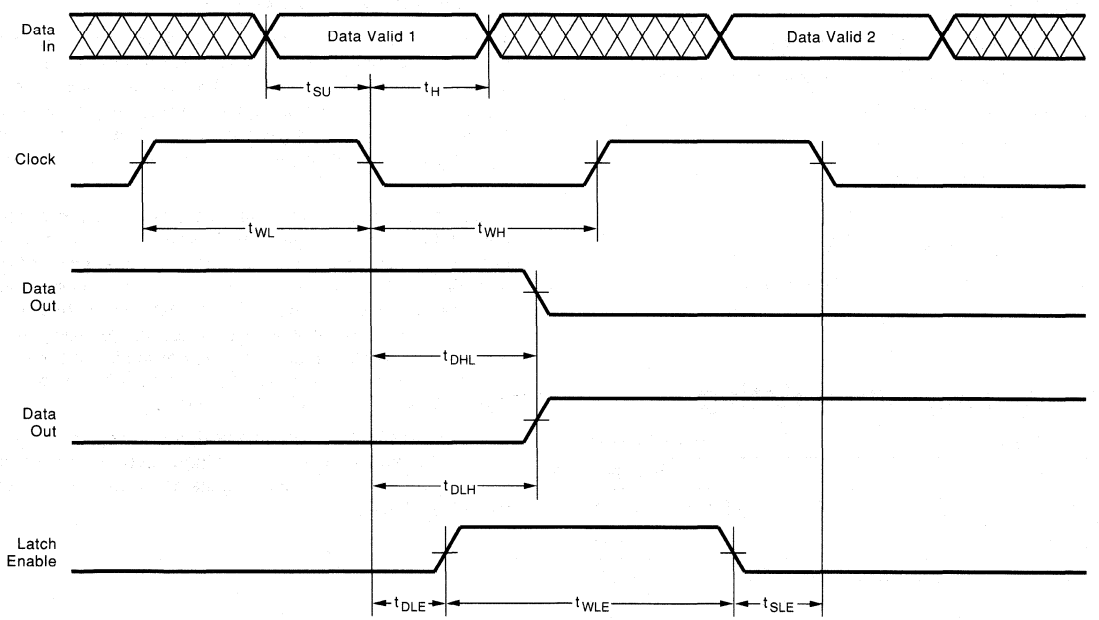
H = V_{PP}

L = GND

Input and Output Equivalent Circuit



Switching Waveforms



32-Channel Serial To Parallel Converter With Open Drain Outputs

Ordering Information

Device	Package Options				
	44 J-Lead Quad Ceramic Chip Carrier	44 J-Lead Quad Plastic Chip Carrier	44 Lead Quad Plastic Gullwing	Die	44 J-Lead Quad Ceramic Chip Carrier (MIL-STD-883 Processed*)
HV51	HV5122DJ	HV5122PJ	HV5122PG	HV5122X	RBHV5122DJ
HV52	HV5222DJ	HV5222PJ	HV5222PG	HV5222X	RBHV5222DJ

* For Hi-Rel process flows, please refer to perfer to page 5-3 in the Databook

Features

- ☐ Processed with HVCMOS® technology
- ☐ Output voltages to 225V using a ramped supply voltage
- ☐ Sink current minimum 100mA
- ☐ Shift register speed 8MHz
- ☐ Strobe and enable inputs
- ☐ CMOS compatible inputs
- ☐ Forward and reverse shifting options
- ☐ 44-lead ceramic surface mount package
- ☐ Hi-Rel processing available

Absolute Maximum Ratings

Supply voltage, V_{DD}[1]		-0.5V to +15V
Output voltage, V_{PP}[2]		-0.5V to +250V
Logic input levels		-0.5V to V_{DD} + 0.5V
Ground currrent[3]		1.5A
Continuous total power dissipation[4]	Ceramic Plastic	1500mW 1200mW
Operating temperature range	Commerical Military	-40°C to +85°C -55 to +125°C
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. All voltages are referenced to GND.
2. These devices have been designed to be used in applications which either switch the V_{PP} supply to ground before changing the state of the high voltage outputs or limit the current through each output.
3. Duty cycle is limited by the total power dissipated in the package.
4. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

General Description

The HV51 and HV52 are low voltage serial to high voltage parallel converters wtih open drain outputs. These devices have been designed for use as drivers for AC electroluminescent displays. They can also be used in any application requiring multiple output high voltage current sinking capabilities such as driving inkjet and electrostatic print heads, plasma panels, vacuum fluorescent, or large matrix LCD displays.

These devices consist of a 32-bit shift register and control logic to perform the Output Enable and All-ON functions. Data is shifted through the shift register on the high to low transition of the clock. The HV51 shifts in the counterclockwise direction when viewed from the top of the package and the HV52 shifts in the clockwise direction. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register. Operation of the shift register is not affected by the OE (Output Enable) or the STR (Strobe) inputs.

The HV51 and HV52 have been designed to be used in systems which either switch off the high voltage supply before changing the state of the high voltage outputs or which limit the current through each output.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Typ	Max	Units	Conditions
I_{DD}	V_{DD} supply current				15	mA	f_{CLK} = 8MHz F_{DATA} = 4MHz
I_{DDQ}	Quiescent V_{DD} supply current				100	µA	All V_{IN} = 0V
$I_{O(OFF)}$	Off state output current				10	µA	All outputs high All SWS parallel
I_{IH}	High-level logic input current				1	µA	V_{IH} = 12V
I_{IL}	Low-level logic input current				-1	µA	V_{IL} = 0V
V_{OH}	High-level output data out		V_{DD} - 1.0V			V	I_{Dout} = -100µA
V_{OL}	Low-level output voltage	HV_{OUT}			15.0	V	I_{HVout} = +100mA
		Data out			1.0	V	I_{Dout} = +100µA
V_{OC}	HV_{OUT} Clamp Voltage				-1.5	V	I_{OL} = -100mA

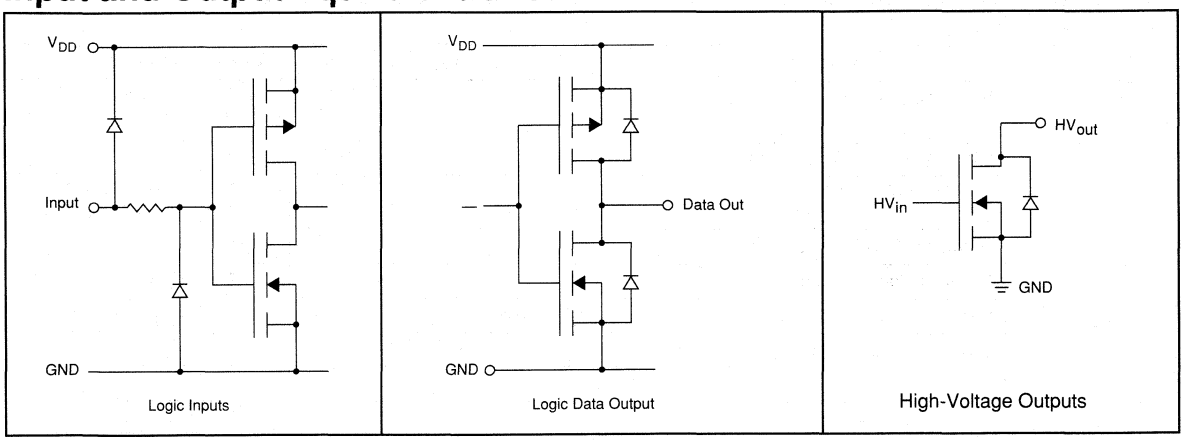
AC Characteristics (V_{DD} = 12V, T_C = 25°C)

Symbol	Parameter	Min	Typ	Max	Units	Conditions
f_{CLK}	Clock frequency			8	MHz	
t_W	Clock width high or low	62			ns	
t_{SU}	Data set-up time before clock falls	25			ns	
t_H	Data hold time after clock falls	10			ns	
t_{ON}	Turn ON time, HV_{OUT} from enable			500	ns	R_L = 2KΩ to 200V
t_{DHL}	Delay time clock to data high to low			100	ns	
t_{DLH}	Delay time clock to data low to high			100	ns	

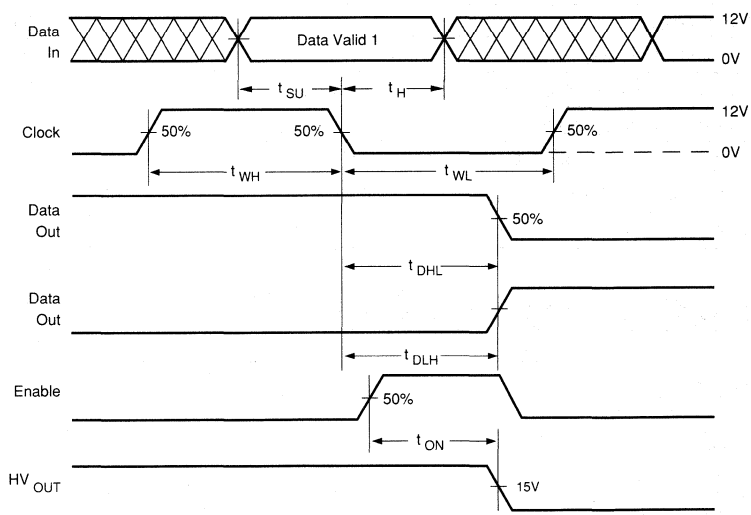
Recommended Operating Conditions

Symbol	Parameter		Min	Typ	Max	Units
V_{DD}	Logic supply voltage		10.8	12	13.2	V
V_{PP}	High voltage supply		8.0		225	V
V_{IH}	High-level input voltage		V_{DD} - 2V		V_{DD}	V
V_{IL}	Low-level input voltage		0		2.0	V
f_{CLK}	Clock frequency				8	MHz
T_A	Operating free-air temperature	Commercial	-40		+85	°C
		Military Hi-Rel (RB)	-55		+125	°C

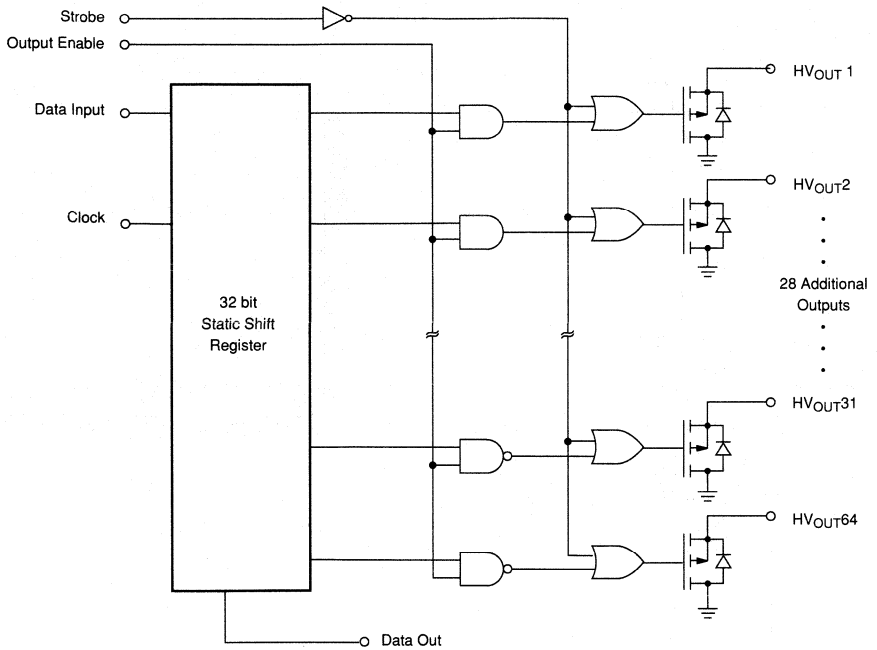
Input and Output Equivalent Circuits



Switching Waveforms



Functional Block Diagram



Function Table

Function	Inputs				Outputs		
	DI	CLK	OE	STR	Shift Reg 1 2...32	HV Outputs 1 2...32	Data Out *
All on	X	X	X	L	* *...*	L L...L	*
All off	X	X	L	H	* *...*	H H...H	*
Load S/R	H or L	↓	L	H	H or L *...*	H H...H	
Output enable	X	H or L	H	H	H or L *...*	L or H *...*	*

Notes:
X = Don't care
* = Dependent on previous stage's state before the last CLK : High to low transition.
↓ = High to low transition
H = High level
L = Low level

Pin Configurations

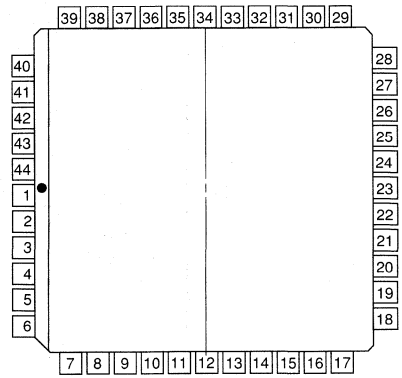
HV51
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 16	23	Output Enable
2	HV_{OUT} 17	24	Clock
3	HV_{OUT} 18	25	GND
4	HV_{OUT} 19	26	V_{DD}
5	HV_{OUT} 20	27	Stobe
6	HV_{OUT} 21	28	Data In
7	HV_{OUT} 22	29	N/C
8	HV_{OUT} 23	30	HV_{OUT} 1
9	HV_{OUT} 24	31	HV_{OUT} 2
10	HV_{OUT} 25	32	HV_{OUT} 3
11	HV_{OUT} 26	33	HV_{OUT} 4
12	HV_{OUT} 27	34	HV_{OUT} 5
13	HV_{OUT} 28	35	HV_{OUT} 6
14	HV_{OUT} 29	36	HV_{OUT} 7
15	HV_{OUT} 30	37	HV_{OUT} 8
16	HV_{OUT} 31	38	HV_{OUT} 9
17	HV_{OUT} 32	39	HV_{OUT} 10
18	Data Out	40	HV_{OUT} 11
19	N/C	41	HV_{OUT} 12
20	N/C	42	HV_{OUT} 13
21	N/C	43	HV_{OUT} 14
22	NC	44	HV_{OUT} 15

HV52
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 17	23	Output Enable
2	HV_{OUT} 16	24	Clock
3	HV_{OUT} 15	25	GND
4	HV_{OUT} 14	26	V_{DD}
5	HV_{OUT} 13	27	Strobe
6	HV_{OUT} 12	28	Data In
7	HV_{OUT} 11	29	N/C
8	HV_{OUT} 10	30	HVout 32
9	HV_{OUT} 9	31	HV_{OUT} 31
10	HV_{OUT} 8	32	HV_{OUT} 30
11	HV_{OUT} 7	33	HV_{OUT} 29
12	HV_{OUT} 6	34	HV_{OUT} 28
13	HV_{OUT} 5	35	HV_{OUT} 27
14	HV_{OUT} 4	36	HV_{OUT} 26
15	HV_{OUT} 3	37	HV_{OUT} 25
16	HV_{OUT} 2	38	HV_{OUT} 24
17	HV_{OUT} 1	39	HV_{OUT} 23
18	Data Out	40	HV_{OUT} 22
19	N/C	41	HV_{OUT} 21
20	N/C	42	HV_{OUT} 20
21	N/C	43	HV_{OUT} 19
22	N/C	44	HV_{OUT} 18

Package Outline



top view

44-pin J-lead Package

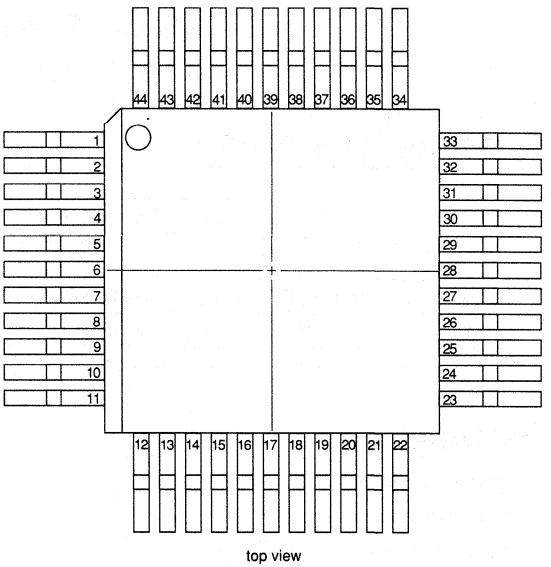
Pin Configurations

HV51

44-Pin Quad Plastic Package

Pin	Function	Pin	Function
1	HV_{OUT} 11	23	Data Out
2	HV_{OUT} 12	24	N/C
3	HV_{OUT} 13	25	N/C
4	HV_{OUT} 14	26	N/C
5	HV_{OUT} 15	27	N/C
6	HV_{OUT} 16	28	Output Enable
7	HV_{OUT} 17	29	CLK
8	HV_{OUT} 18	30	V_{SS}
9	HV_{OUT} 19	31	V_{DD}
10	HV_{OUT} 20	32	Strobe
11	HV_{OUT} 21	33	Data In
12	HV_{OUT} 22	34	N/C
13	HV_{OUT} 23	35	HV_{OUT} 1
14	HV_{OUT} 24	36	HV_{OUT} 2
15	HV_{OUT} 25	37	HV_{OUT} 3
16	HV_{OUT} 26	38	HV_{OUT} 4
17	HV_{OUT} 27	39	HV_{OUT} 5
18	HV_{OUT} 28	40	HV_{OUT} 6
19	HV_{OUT} 29	41	HV_{OUT} 7
20	HV_{OUT} 30	42	HV_{OUT} 8
21	HV_{OUT} 31	43	HV_{OUT} 9
22	HV_{OUT} 32	44	HV_{OUT} 10

Package Outline



44-pin Quad Plastic Package

HV52

44-Pin Quad Plastic Package

Pin	Function	Pin	Function
1	HV_{OUT} 22	23	Data Out
2	HV_{OUT} 21	24	N/C
3	HV_{OUT} 20	25	N/C
4	HV_{OUT} 19	26	N/C
5	HV_{OUT} 18	27	N/C
6	HV_{OUT} 17	28	Output Enable
7	HV_{OUT} 16	29	CLK
8	HV_{OUT} 15	30	V_{SS}
9	HV_{OUT} 14	31	V_{DD}
10	HV_{OUT} 13	32	Strobe
11	HV_{OUT} 12	33	Data In
12	HV_{OUT} 11	34	N/C
13	HV_{OUT} 10	35	HV_{OUT} 32
14	HV_{OUT} 9	36	HV_{OUT} 31
15	HV_{OUT} 8	37	HV_{OUT} 30
16	HV_{OUT} 7	38	HV_{OUT} 29
17	HV_{OUT} 6	39	HV_{OUT} 28
18	HV_{OUT} 5	40	HV_{OUT} 27
19	HV_{OUT} 4	41	HV_{OUT} 26
20	HV_{OUT} 3	42	HV_{OUT} 25
21	HV_{OUT} 2	43	HV_{OUT} 24
22	HV_{OUT} 1	44	HV_{OUT} 23

32-Channel Serial To Parallel Converter With High Voltage Push-Pull Outputs

Ordering Information

Device	Package Options				
	44 J-Lead Quad Ceramic Chip Carrier	44 J-Lead Quad Plastic Chip Carrier	44 Lead Quad Plastic Gullwing	Die	44 J-Lead Quad Ceramic Chip Carrier (MIL-STD-883 Processed*)
HV53	HV5308DJ	HV5308PJ	HV5308PG	HV5308X	RBHV5308DJ
HV54	HV5408DJ	HV5408PJ	HV5408PG	HV5408X	RBHV5408DJ

* For Hi-Rel process flows, please refer to perfer to page 5-3 in the Databook

Features

- ☐ Processed with HVCMOS® technology
- ☐ Low power level shifting
- ☐ Source/sink current minimum 20mA
- ☐ Shift register speed 8MHz
- ☐ Latched data outputs
- ☐ CMOS compatible inputs
- ☐ Forward and reverse shifting options
- ☐ Diode to V_{PP} allows efficient power recovery

Absolute Maximum Ratings[1]

Supply voltage, V_{DD}[2]		-0.5V to +16V
Supply voltage, V_{PP}		-0.5V to +80V
Logic input levels[2]		-0.5 to V_{DD} + 0.5V
Ground currrent[3]		1.5A
Continuous total power dissipation[4]	Ceramic	1500mW
	Plastic	1200mW
Operating temperature range	Commerical	-40°C to +85°C
	Military	-55°C to 125°C
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. Device will survive (but operation may not be specified or guaranteed) at these extremes.
2. All voltages are referenced to GND.
3. Duty cycle is limited by the total power dissipated in the package.
4. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

General Description

The HV53 and HV54 are low voltage serial to high voltage parallel converters wtih push-pull outputs. These devices have been designed for use as drivers for AC-electroluminescent displays. They can also be used in any application requiring multiple output high voltage current sourcing and sinking capabilities such as driving plasma panels, vacuum fluorescent, or large matrix LCD displays.

These devices consist of a 32-bit shift register, 32 latches, and control logic to enable outputs. Q1 is connected to the first stage of the shift register through the Output Enable logic. Data is shifted through the shift register on the low to high transition of the clock. The HV54 shifts in the counterclockwise direction when viewed from the top of the package and the HV53 shifts in the clockwise direction. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register (32). Operation of the shift register is not affected by the LE (latch enable) or the OE (output enable) inputs. Transfer of data from the shift register to the latch occurs when the LE input is high. The data in the latch is retained when LE is low.

Electrical Characteristics (V_{PP} = 60V, V_{DD} = 12V, T_A =25°C)

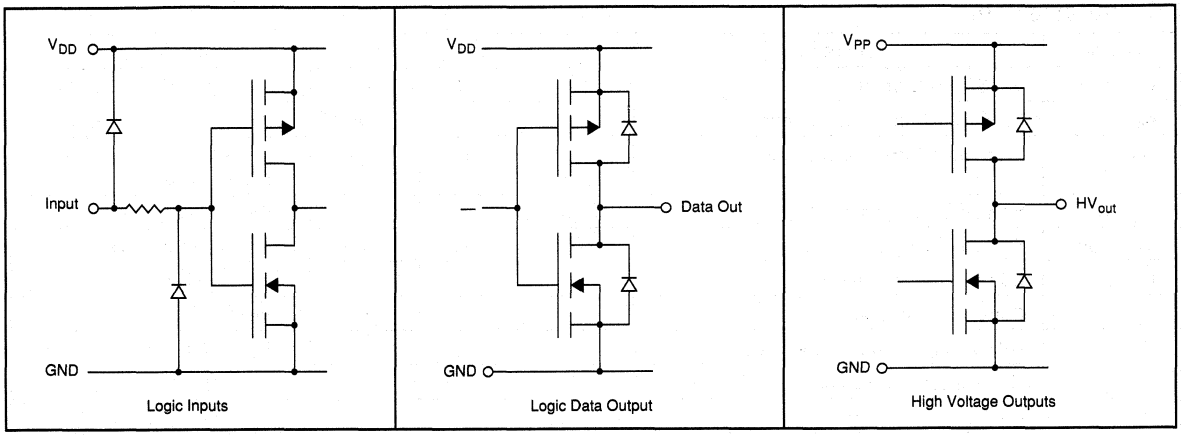
DC Characteristics

Symbol	Parameter	Min	Max	Units	Conditions
I_{PP}	V_{PP} Supply Current		0.5	mA	HVoutputs HIGH to LOW
I_{DDQ}	I_{DD} Supply Current (Quiescent)		100	µA	All inputs = V_{DD} or GND
I_{DD}	I_{DD} Supply Current (Operating)		15	mA	V_{DD} = V_{DD} max, f_{CLK} = 8 MHz
V_{OH} (Data)	Shift Register Output Voltage	10.5		V	When driving HIGH
V_{OL} (Data)	Shift Register Output Voltage		1	V	When driving LOW
I_{IH}	Current Leakage, any input		1	µA	Input = HIGH
I_{IL}	Current Leakage, any input		-1	µA	Input = LOW
V_{OC}	HV Output Clamp Diode Voltage		-1.5	V	I_{OL} = -100mA
V_{OH}	HV Output when Sourcing	52		V	I_{OH} = -20mA, -40 to 85°C
V_{OL}	HV Output when Sinking		8	V	I_{OL} = 20mA, -40 to 85°C
V_{OH}	HV Output when Sourcing	52		V	I_{OH} = -15mA, -55 to 125°C
V_{OL}	HV Output when Sinking		8	V	I_{OL} = 15mA, -55 to 125°C

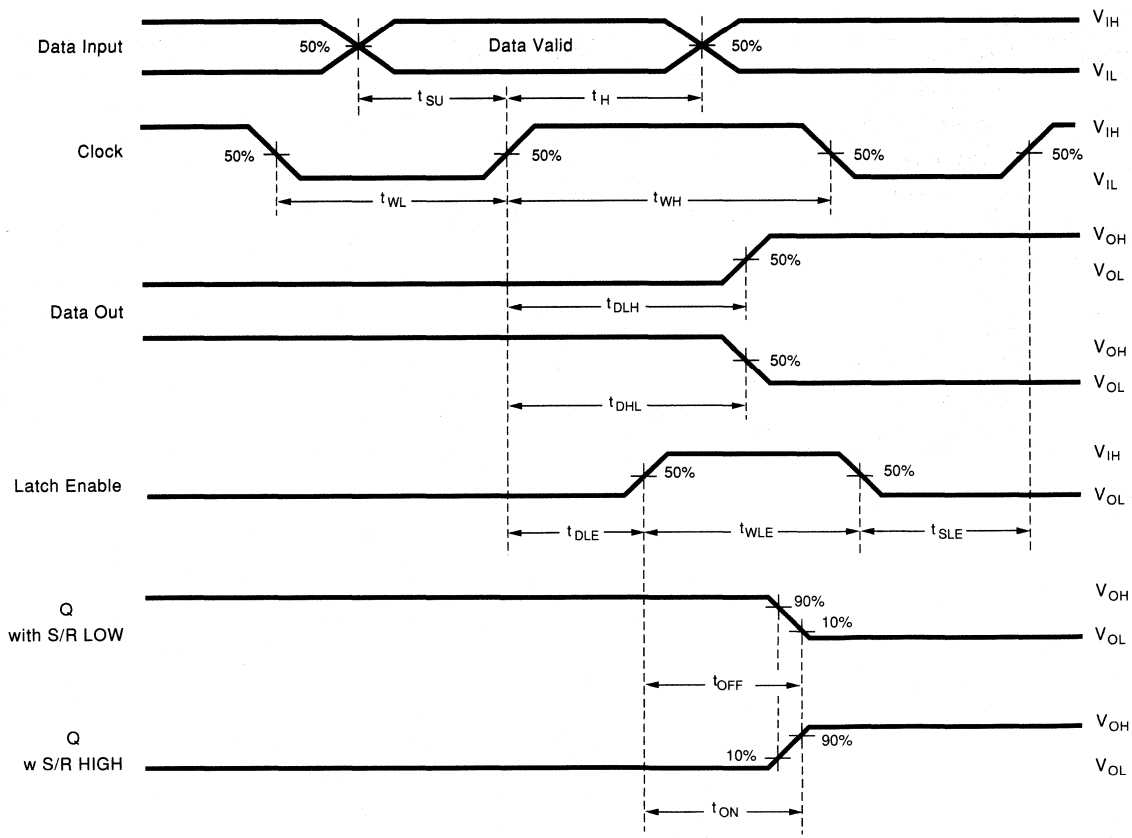
AC Characteristics

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock Frequency		8	MHz	
t_{WL} or t_{WH}	Clock width, HIGH or LOW	62		ns	
t_{SU}	Setup time before CLK rises	25		ns	
t_H	Hold time after CLK rises	10		ns	
t_{DLH} (Data)	Data Output Delay after L to H CLK		100	ns	C_L = 15pF
t_{DHL} (Data)	Data Output Delay after H to L CLK		100	ns	C_L = 15pF
t_{DLE}	LE Delay after L to H CLK	50		ns	
t_{WLE}	Width of LE Pulse	50		ns	
t_{SLE}	LE Setup Time before L to H CLK	50		ns	
t_{ON}	Delay from LE to HV_{OUT}, L to H		500	ns	
t_{OFF}	Delay from LE to HV_{OUT}, H to L		500	ns	

Input and Output Equivalent Circuits



Switching Waveforms



Recommended Operating Conditions

(over -40 to 85°C for commercial temperature range and -55°C to 125°C for military)

Symbol	Parameter	Min	Max	Units	Comments
V_{DD}	Logic Voltage Supply	10.8	13.2	V	
V_{PP}	High Voltage Supply	8.0	80	V	HV5308 and HV5408
V_{IH}	Input HIGH Voltage	V_{DD}-2	V_{DD}	V	
V_{IL}	Input LOW Voltage	0	2	V	
f_{CLK}	Clock Frequency	0	8	MHz	

Note:

Power-up sequence should be the following:

1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

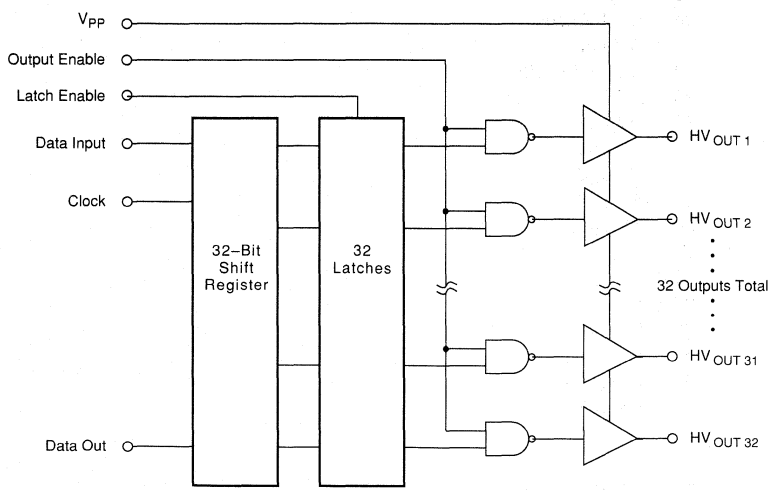
Function Tables

Data Input	CLK*	Data Output
H	⎍	H
L	⎍	L
X	No ⎍	No Change

* ⎍ = LOW-to-HIGH level transition

Data Input	LE	OE	HV Output
X	X	L	All HV_{OUT} = LOW
X	L	H	Previous Latched Data
H	H	H	H
L	H	H	L

Functional Block Diagram



Pin Configuration

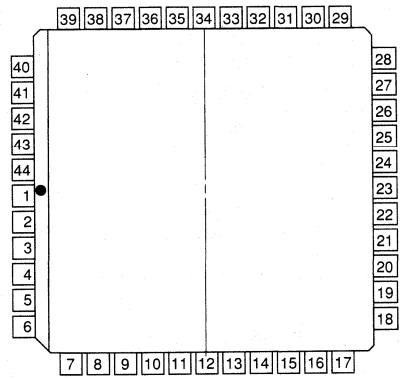
HV53
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 17	23	GND
2	HV_{OUT} 16	24	V_{PP}
3	HV_{OUT} 15	25	V_{DD}
4	HV_{OUT} 14	26	Latch Enable
5	HV_{OUT} 13	27	Data In
6	HV_{OUT} 12	28	Output Enable
7	HV_{OUT} 11	29	N/C
8	HV_{OUT} 10	30	HV_{OUT} 32
9	HV_{OUT} 9	31	HV_{OUT} 31
10	HV_{OUT} 8	32	HV_{OUT} 30
11	HV_{OUT} 7	33	HV_{OUT} 29
12	HV_{OUT} 6	34	HV_{OUT} 28
13	HV_{OUT} 5	35	HV_{OUT} 27
14	HV_{OUT} 4	36	HV_{OUT} 26
15	HV_{OUT} 3	37	HV_{OUT} 25
16	HV_{OUT} 2	38	HV_{OUT} 24
17	HV_{OUT} 1	39	HV_{OUT} 23
18	Data Out	40	HV_{OUT} 22
19	N/C	41	HV_{OUT} 21
20	N/C	42	HV_{OUT} 20
21	N/C	43	HV_{OUT} 19
22	Clock	44	HV_{OUT} 18

HV54
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT}16	23	GND
2	HV_{OUT}17	24	V_{PP}
3	HV_{OUT}18	25	V_{DD}
4	HV_{OUT}19	26	Latch Enable
5	HV_{OUT}20	27	Data In
6	HV_{OUT}21	28	Output Enable
7	HV_{OUT}22	29	N/C
8	HV_{OUT}23	30	HV_{OUT}1
9	HV_{OUT}24	31	HV_{OUT}2
10	HV_{OUT}25	32	HV_{OUT}3
11	HV_{OUT}26	33	HV_{OUT}4
12	HV_{OUT}27	34	HV_{OUT}5
13	HV_{OUT}28	35	HV_{OUT}6
14	HV_{OUT}29	36	HV_{OUT}7
15	HV_{OUT}30	37	HV_{OUT}8
16	HV_{OUT}31	38	HV_{OUT}9
17	HV_{OUT}32	39	HV_{OUT}10
18	Data Out	40	HV_{OUT}11
19	N/C	41	HV_{OUT}12
20	N/C	42	HV_{OUT}13
21	N/C	43	HV_{OUT}14
22	Clock	44	HV_{OUT}15

Package Outline



top view

44-pin J-lead Package

32-Channel Serial To Parallel Converter With Open Drain Outputs

Ordering Information

Device	Recommended Operating V_{PP} max	Package Options			
		44 J-Lead Quad Ceramic Chip Carrier	44 J-Lead Quad Plastic Chip Carrier	44 Lead Quad Plastic Gullwing	Dice
HV55	300V	HV5530DJ	HV5530PJ	HV5530PG	HV5530X
	220V	HV5522DJ	HV5522PJ	HV5522PG	HV5522X
HV56	300V	HV5630DJ	HV5630PJ	HV5630PG	HV5630X
	220V	HV5622DJ	HV5622PJ	HV5622PG	HV5622X

* For Hi-Rel process flows, please refer to page 5-3 in the Databook.

Features

- ☐ Processed with HVCMOS® technology
- ☐ Sink current minimum 100mA
- ☐ Shift register speed 8MHz
- ☐ Polarity and Blanking inputs
- ☐ CMOS compatible inputs
- ☐ Forward and reverse shifting options
- ☐ Diode to V_{PP} allows efficient power recovery
- ☐ 44-lead ceramic surface mount package
- ☐ Hi-Rel processing available

Absolute Maximum Ratings

Supply voltage, V_{DD}[1]		-0.5V to +15V
Output voltage, V_{PP}[1]	HV5530/HV5630	-0.5V to +315V
	HV5522/HV5622	-0.5V to +220V
Logic input levels[1]		-0.5V to V_{DD} + 0.5V
Ground currrent[2]		1.5A
Continuous total power dissipation[4]	Ceramic	1500mW
	Plastic	1200mW
Operating temperature range	Ceramic	-40°C to +85°C
	Plastic	0°C to +70°C
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. All voltages are referenced to V_{SS}.
2. Duty cycle is limited by the total power dissipated in the package.
3. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

General Description

The HV55 and HV56 are low-voltage serial to high-voltage parallel converters wtih open drain outputs. These devices have been designed for use as drivers for AC-electroluminescent displays. They can also be used in any application requiring multiple output high voltage current sinking capabilities such as driving inkjet and electrostatic print heads, plasma panels, vacuum fluorescent, or large matrix LCD displays.

These devices consist of a 32-bit shift register, 32 latches, and control logic to perform the polarity select and blanking of the outputs. Data is shifted through the shift register on the high to low transition of the clock. The HV55 shifts in the counterclockwise direction when viewed from the top of the package, and the HV56 shifts in the clockwise direction. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register. Operation of the shift register is not affected by the $\overline{LE}$ (latch enable), $\overline{BL}$ (blanking), or the $\overline{POL}$ (polarity) inputs. Transfer of data from the shift register to the latch occurs when the $\overline{LE}$ (latch enable) input is high. The data in the latch is stored when $\overline{LE}$ is low.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Max	Units	Conditions
I_{DD}	V_{DD} supply current			15	mA	f_{CLK} = 8MHz F_{DATA} = 4MHz
I_{DDQ}	Quiescent V_{DD} supply current			100	µA	V_{IN} = 0V
$I_{O(OFF)}$	Off state output current			10	µA	All outputs high All SWS parallel
I_{IH}	High-level logic input current			1	µA	$V_{IH} = V_{DD}$
I_{IL}	Low-level logic input current			-1	µA	V_{IL} = 0V
V_{OH}	High-level output data out		V_{DD} - 1.0V		V	I_{Dout} = -100µA
V_{OL}	Low-level output voltage	HV_{OUT}		15.0	V	I_{HVout} = +100mA
		Data out		1.0	V	I_{Dout} = +100µA
V_{OC}	HV_{OUT} clamp voltage			-1.5	V	I_{OL} = -100mA

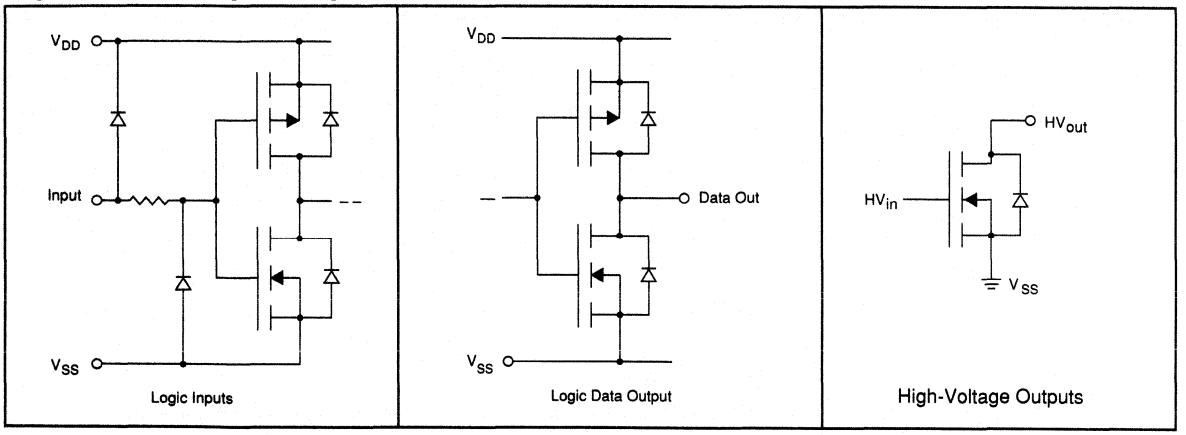
AC Characteristics (V_{DD} = 12V, T_C = 25°C)

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock frequency		8	MHz	
t_W	Clock width high or low	62		ns	
t_{SU}	Data set-up time before clock falls	25		ns	
t_H	Data hold time after clock falls	10		ns	
t_{ON}	Turn on time, HV_{OUT} from enable		500	ns	R_L = 2KΩ to V_{PP} MAX
t_{DHL}	Delay time clock to data high to low		100	ns	C_L = 15pF
t_{DLH}	Delay time clock to data low to high		100	ns	C_L = 15pF
t_{DLE}	Delay time clock to LE low to high	50		ns	
t_{WLE}	Width of LE pulse	50		ns	
t_{SLE}	LE set-up time before clock falls	50		ns	

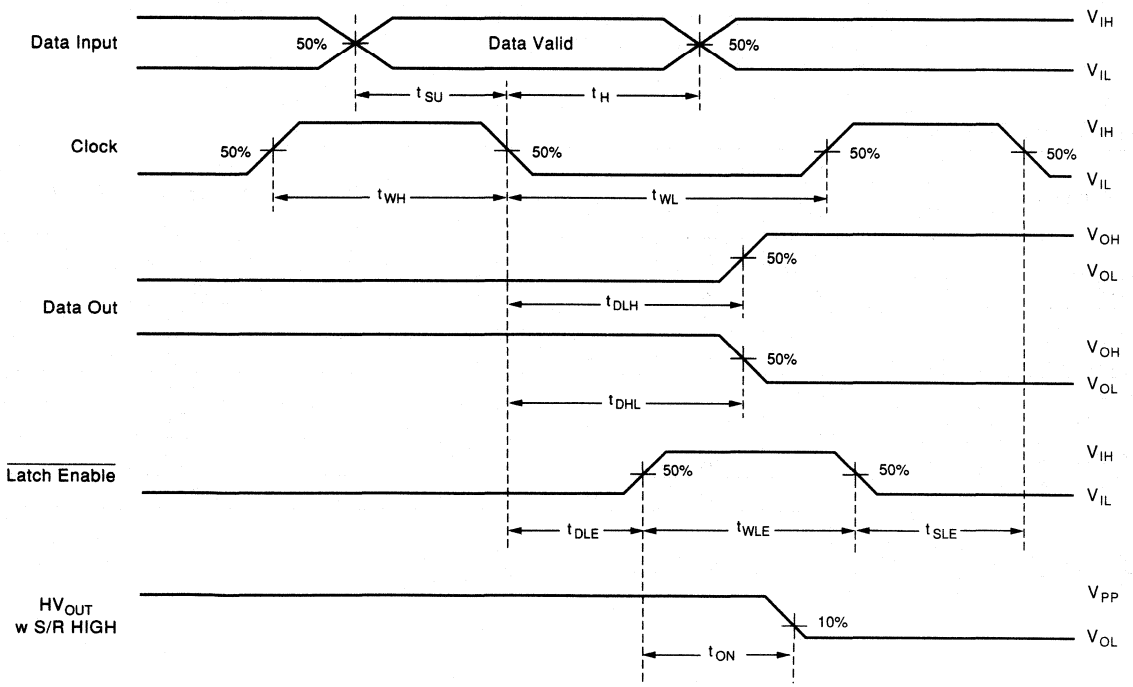
Recommended Operating Conditions

Symbol	Parameter		Min	Max	Units
V_{DD}	Logic supply voltage		10.8	13.2	V
V_{PP}	High voltage supply	HV5530 and HV5630	8	+300	V
		HV5522 and HV5622	8	+220	V
V_{IH}	High-level input voltage		V_{DD} - 2V	V_{DD}	V
V_{IL}	Low-level input voltage		0	2.0	V
f_{CLK}	Clock frequency			8	MHz
T_A	Operating free-air temperature	Commercial	0	+70	°C
		Military Hi-Rel (RB)	-55	+125	°C

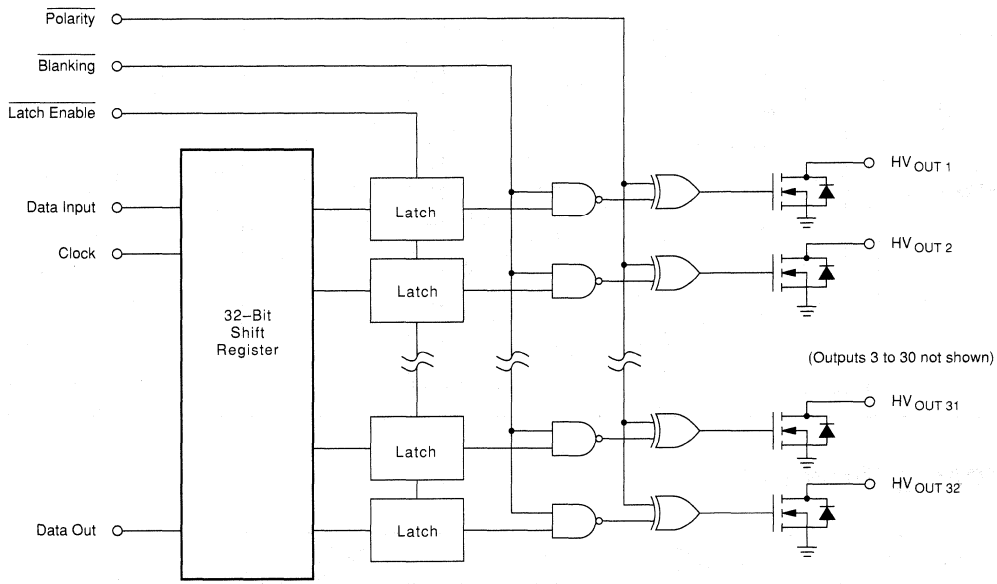
Input and Output Equivalent Circuits



Switching Waveforms



Functional Block Diagram



Function Table

Function	Inputs					Outputs		
	Data	CLK	$\overline{LE}$	$\overline{BL}$	$\overline{POL}$	Shift Reg 1 2...32	HV Outputs 1 2...32	Data Out *
All on	X	X	X	L	L	* *...*	On On...On	*
All off	X	X	X	L	H	* *...*	Off Off...Off	*
Invert mode	X	X	L	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Load S/R	H or L	↓	L	H	H	H or L *...*	* *...*	*
Load Latches	X	H or L	↑	H	H	* *...*	* *...*	*
	X	H or L	↑	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Transparent Latch mode	L	↓	H	H	H	L *...*	Off *...*	*
	H	↓	H	H	H	H *...*	On *...*	*

Notes:
H = high level, L = low level, X = irrelevant, ↓ = high-to-low transition.
* = dependent on previous stage's state before the last CLK ↓ or last LE high.

Pin Configurations

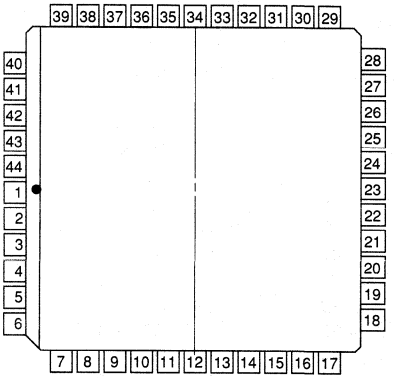
HV55
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 16	23	Clock
2	HV_{OUT} 17	24	V_{SS}
3	HV_{OUT} 18	25	V_{DD}
4	HV_{OUT} 19	26	Latch Enable
5	HV_{OUT} 20	27	Data In
6	HV_{OUT} 21	28	Blanking
7	HV_{OUT} 22	29	N/C
8	HV_{OUT} 23	30	HV_{OUT} 1
9	HV_{OUT} 24	31	HV_{OUT} 2
10	HV_{OUT} 25	32	HV_{OUT} 3
11	HV_{OUT} 26	33	HV_{OUT} 4
12	HV_{OUT} 27	34	HV_{OUT} 5
13	HV_{OUT} 28	35	HV_{OUT} 6
14	HV_{OUT} 29	36	HV_{OUT} 7
15	HV_{OUT} 30	37	HV_{OUT} 8
16	HV_{OUT} 31	38	HV_{OUT} 9
17	HV_{OUT} 32	39	HV_{OUT} 10
18	Data Out	40	HV_{OUT} 11
19	N/C	41	HV_{OUT} 12
20	N/C	42	HV_{OUT} 13
21	N/C	43	HV_{OUT} 14
22	Polarity	44	HV_{OUT} 15

HV56
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 17	23	Clock
2	HV_{OUT} 16	24	V_{SS}
3	HV_{OUT} 15	25	V_{DD}
4	HV_{OUT} 14	26	Latch Enable
5	HV_{OUT} 13	27	Data In
6	HV_{OUT} 12	28	Blanking
7	HV_{OUT} 11	29	N/C
8	HV_{OUT} 10	30	HV_{OUT} 32
9	HV_{OUT} 9	31	HV_{OUT} 31
10	HV_{OUT} 8	32	HV_{OUT} 30
11	HV_{OUT} 7	33	HV_{OUT} 29
12	HV_{OUT} 6	34	HV_{OUT} 28
13	HV_{OUT} 5	35	HV_{OUT} 27
14	HV_{OUT} 4	36	HV_{OUT} 26
15	HV_{OUT} 3	37	HV_{OUT} 25
16	HV_{OUT} 2	38	HV_{OUT} 24
17	HV_{OUT} 1	39	HV_{OUT} 23
18	Data Out	40	HV_{OUT} 22
19	N/C	41	HV_{OUT} 21
20	N/C	42	HV_{OUT} 20
21	N/C	43	HV_{OUT} 19
22	Polarity	44	HV_{OUT} 18

Package Outline



top view

44-pin J-lead Package

Pin Configurations

HV55

44-Pin Quad Plastic Gullwing Package

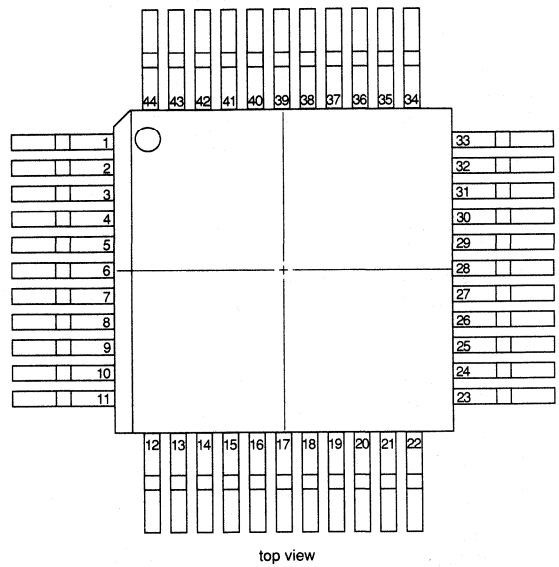
Pin	Function	Pin	Function
1	HV_{OUT} 11	23	Data Out
2	HV_{OUT} 12	24	N/C
3	HV_{OUT} 13	25	N/C
4	HV_{OUT} 14	26	N/C
5	HV_{OUT} 15	27	Polarity
6	HV_{OUT} 16	28	Clock
7	HV_{OUT} 17	29	V_{SS}
8	HV_{OUT} 18	30	V_{DD}
9	HV_{OUT} 19	31	Latch Enable
10	HV_{OUT} 20	32	Data In
11	HV_{OUT} 21	33	Blanking
12	HV_{OUT} 22	34	N/C
13	HV_{OUT} 23	35	HV_{OUT} 1
14	HV_{OUT} 24	36	HV_{OUT} 2
15	HV_{OUT} 25	37	HV_{OUT} 3
16	HV_{OUT} 26	38	HV_{OUT} 4
17	HV_{OUT} 27	39	HV_{OUT} 5
18	HV_{OUT} 28	40	HV_{OUT} 6
19	HV_{OUT} 29	41	HV_{OUT} 7
20	HV_{OUT} 30	42	HV_{OUT} 8
21	HV_{OUT} 31	43	HV_{OUT} 9
22	HV_{OUT} 32	44	HV_{OUT} 10

HV56

44-Pin Quad Plastic Gullwing Package

Pin	Function	Pin	Function
1	HV_{OUT} 22	23	Data Out
2	HV_{OUT} 21	24	N/C
3	HV_{OUT} 20	25	N/C
4	HV_{OUT} 19	26	N/C
5	HV_{OUT} 18	27	Polarity
6	HV_{OUT} 17	28	Clock
7	HV_{OUT} 16	29	V_{SS}
8	HV_{OUT} 15	30	V_{DD}
9	HV_{OUT} 14	31	Latch Enable
10	HV_{OUT} 13	32	Data In
11	HV_{OUT} 12	33	Blanking
12	HV_{OUT} 11	34	N/C
13	HV_{OUT} 10	35	HV_{OUT} 32
14	HV_{OUT} 9	36	HV_{OUT} 31
15	HV_{OUT} 8	37	HV_{OUT} 30
16	HV_{OUT} 7	38	HV_{OUT} 29
17	HV_{OUT} 6	39	HV_{OUT} 28
18	HV_{OUT} 5	40	HV_{OUT} 27
19	HV_{OUT} 4	41	HV_{OUT} 26
20	HV_{OUT} 3	42	HV_{OUT} 25
21	HV_{OUT} 2	43	HV_{OUT} 24
22	HV_{OUT} 1	44	HV_{OUT} 23

Package Outline



44-pin Quad Plastic Gullwing Package

32-Channel Serial To Parallel Converter With Push-Pull Outputs

Ordering Information

Device	Package Options			
	44 J-Lead Quad Ceramic Chip Carrier	44 J-Lead Quad Plastic Chip Carrier	Die in waffle pack	44 J-Lead Quad Ceramic Chip Carrier (MIL-STD-883 Processed*)
HV57	HV5708DJ	HV5708PJ	HV5708X	RBHV5708DJ
HV58	HV5808DJ	HV5808PJ	HV5808X	RBHV5808DJ

* For Hi-Rel process flows, refer to page 5-3 of the Databook.

Features

- ☐ Processed with HVCMOS® technology
- ☐ Output voltages up to 80V
- ☐ Low power level shifting
- ☐ Source/sink current minimum 20mA
- ☐ Shift register speed 8MHz
- ☐ Latched data outputs
- ☐ Forward and reverse shifting options
- ☐ Diode to V_{PP} allows efficient power recovery
- ☐ CMOS compatible inputs

Absolute Maximum Ratings[1]

Supply voltage, V_{DD}[2]		-0.5V to +15V
Output voltage, V_{PP}		-0.5V to +80V
Logic input levels[2]		-0.5V to V_{DD} +0.5V
Ground currrent[3]		1.5A
Continuous total power dissipation[4]	Ceramic	1500mW
	Plastic	1200mW
Operating temperature range	Commerical	-40°C to +85°C
	Military	-55°C to +125°C
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. Device will survive (but operation may not be specified or guaranteed) at these extremes.
2. All voltages are referenced to GND.
3. Duty cycle is limited by the total power dissipated in the package.
4. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

General Description

The HV57 and HV58 are low-voltage serial to high-voltage parallel converters wtih push-pull outputs.These devices have been designed for use as drivers for AC-electroluminescent displays. They can also be used in any application requiring multiple output high-voltage current sourcing and sinking capabilities such as driving plasma panels, vacuum fluorescent displays, or large matrix LCD displays. The inputs are fully CMOS compatible.

These devices consist of a 32-bit shift register, 32 latches, and control logic to perform the polarity select and blanking of the outputs. HVout1 is connected to the first stage of the shift register through the polarity and blanking logic. Data is shifted through the shift register on the logic low to high transition of the clock. The HV57 shifts data in the clockwise direction when viewed from the top of the package and the HV58 shifts in the counterclockwise direction. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register (HVout32). Operation of the shift register is not affected by the $\overline{LE}$ (latch enable), $\overline{BL}$ (blanking), or the $\overline{POL}$ (polarity) inputs. Transfer of data from the shift register to the latch occurs when the $\overline{LE}$ (latch enable) input is high. The data in the latch is stored when $\overline{LE}$ is low.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Max	Units	Conditions
I_{DD}	V_{DD} supply current			15	mA	$V_{DD} = V_{DD}$ max f_{CLK} = 8MHz
I_{PP}	High voltage supply current			0.5	mA	Outputs high
				0.5	mA	Outputs low
I_{DDQ}	Quiescent V_{DD} supply current			100	µA	All $V_{IN} = V_{SS}$ or V_{DD}
V_{OH}	High-level output	HV_{OUT}	52		V	I_O= -20mA(-15mA*)
		Data out	10.5		V	I_O= -100µA
V_{OL}	Low-level output	HV_{OUT}		8	V	I_O= 20mA(15mA*)
		Data out		1	V	I_O= 100µA
I_{IH}	High-level logic input current			1	µA	$V_{IH} = V_{DD}$
I_{IL}	Low-level logic input current			-1	µA	V_{IL} = 0V

* Over Military temperature range

AC Characteristics (V_{DD} = 12V, T_C = 25°C)

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock frequency		8	MHz	
t_W	Clock width high or low	62		ns	
t_{SU}	Data set-up time before clock rises	25		ns	
t_H	Data hold time after clock rises	10		ns	
t_{ON}, t_{OFF}	Time from latch enable to HV_{OUT}		500	ns	
t_{DHL}	Delay time clock to data high to low		100	ns	C_L = 15pF
t_{DLH}	Delay time clock to data low to high		100	ns	C_L = 15pF
t_{DLE}	Delay time clock to $\overline{LE}$ low to high	50		ns	
t_{WLE}	Width of $\overline{LE}$ pulse	50		ns	
t_{SLE}	$\overline{LE}$ set-up time before clock rises	50		ns	

Recommended Operating Conditions

Symbol	Parameter		Min	Max	Units
V_{DD}	Logic supply voltage		10.8	15	V
V_{PP}	Output high voltage		8.0	75	V
V_{IH}	High-level input voltage		V_{DD} - 2V	V_{DD}	V
V_{IL}	Low-level input voltage		0	2.0	V
f_{CLK}	Clock frequency			8	MHz
T_A	Operating free-air temperature	Commercial	0	+70	°C
		Military Hi-Rel (RB)	-55	+125	°C

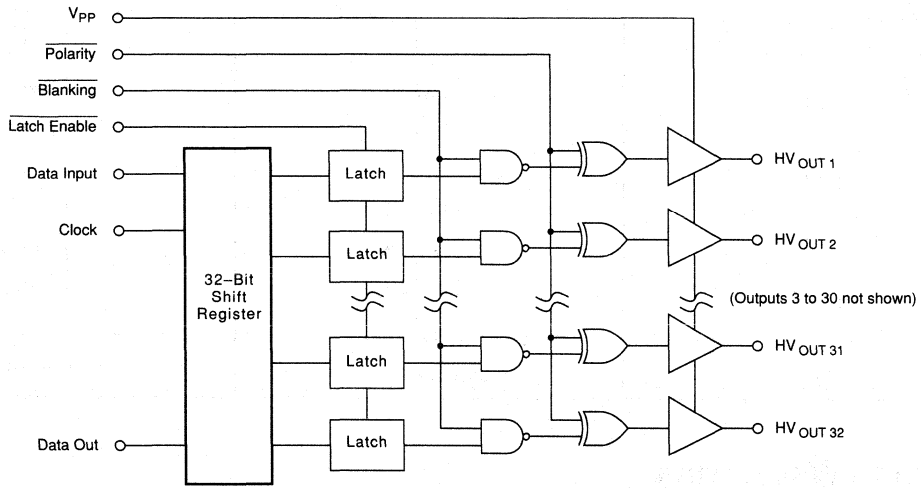
Note:

Power-up sequence should be the following:

1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

Functional Block Diagram

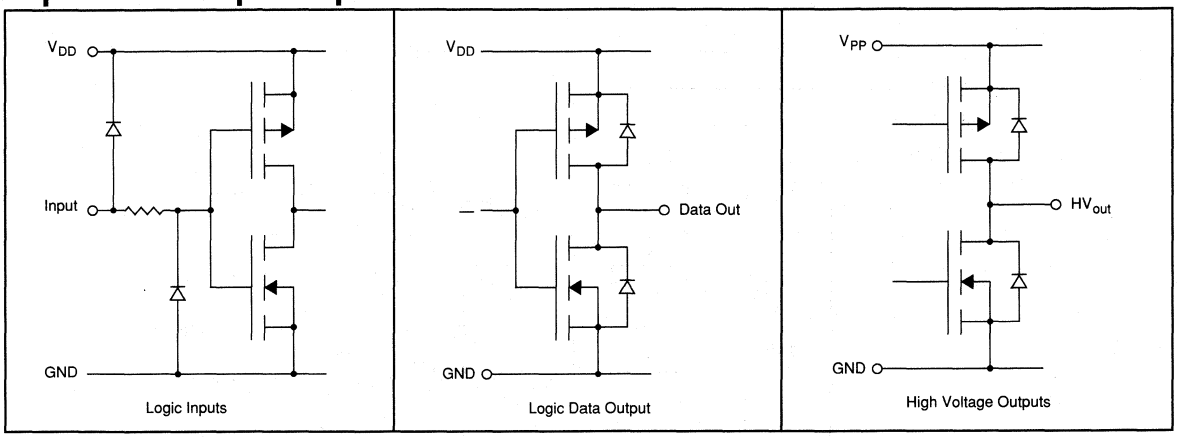


Function Table

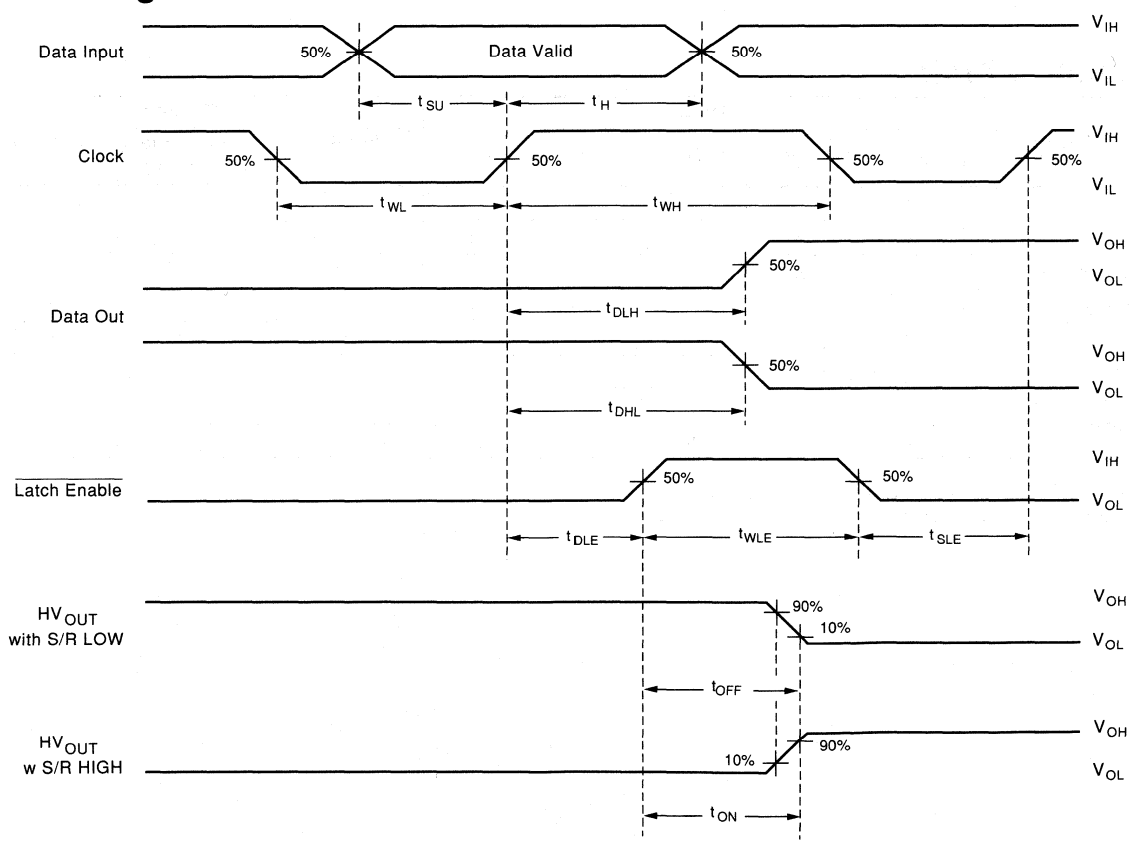
Function	Inputs					Outputs		
	Data	CLK	$\overline{LE}$	$\overline{BL}$	$\overline{POL}$	Shift Reg 1 2...32	HV Outputs 1 2...32	Data Out *
All on	X	X	X	L	L	* *...*	H H...H	*
All off	X	X	X	L	H	* *...*	L L...L	*
Invert mode	X	X	L	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Load S/R	H or L	↑	L	H	H	H or L *...*	* *...*	*
Load latches	X	H or L	↑	H	H	* *...*	* *...*	*
	X	H or L	↑	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Transparent latch mode	L	↑	H	H	H	L *...*	L *...*	*
	H	↑	H	H	H	H *...*	H *...*	*

Notes:
H = high level, L = low level, X = irrelevant, ↑ = low-to-high transition.
* = dependent on previous stage's state before the last CLK or last $\overline{LE}$ high,

Input and Output Equivalent Circuits



Switching Waveforms



Pin Configurations

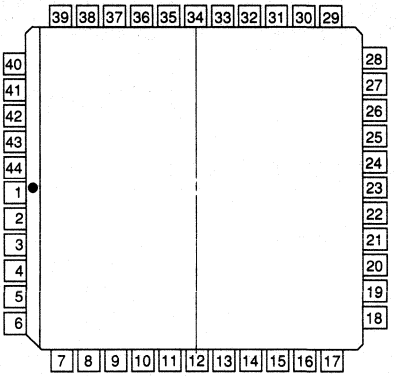
HV57
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 17	23	GND
2	HV_{OUT} 16	24	V_{PP}
3	HV_{OUT} 15	25	V_{DD}
4	HV_{OUT} 14	26	Latch Enable
5	HV_{OUT} 13	27	Data In
6	HV_{OUT} 12	28	Blanking
7	HV_{OUT} 11	29	N/C
8	HV_{OUT} 10	30	HV_{OUT} 32
9	HV_{OUT} 9	31	HV_{OUT} 31
10	HV_{OUT} 8	32	HV_{OUT} 30
11	HV_{OUT} 7	33	HV_{OUT} 29
12	HV_{OUT} 6	34	HV_{OUT} 28
13	HV_{OUT} 5	35	HV_{OUT} 27
14	HV_{OUT} 4	36	HV_{OUT} 26
15	HV_{OUT} 3	37	HV_{OUT} 25
16	HV_{OUT} 2	38	HV_{OUT} 24
17	HV_{OUT} 1	39	HV_{OUT} 23
18	Data Out	40	HV_{OUT} 22
19	N/C	41	HV_{OUT} 21
20	N/C	42	HV_{OUT} 20
21	Polarity	43	HV_{OUT} 19
22	Clock	44	HV_{OUT} 18

HV58
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 16	23	GND
2	HV_{OUT} 17	24	V_{PP}
3	HV_{OUT} 18	25	V_{DD}
4	HV_{OUT} 19	26	Latch Enable
5	HV_{OUT} 20	27	Data In
6	HV_{OUT} 21	28	Blanking
7	HV_{OUT} 22	29	N/C
8	HV_{OUT} 23	30	HV_{OUT} 1
9	HV_{OUT} 24	31	HV_{OUT} 2
10	HV_{OUT} 25	32	HV_{OUT} 3
11	HV_{OUT} 26	33	HV_{OUT} 4
12	HV_{OUT} 27	34	HV_{OUT} 5
13	HV_{OUT} 28	35	HV_{OUT} 6
14	HV_{OUT} 29	36	HV_{OUT} 7
15	HV_{OUT} 30	37	HV_{OUT} 8
16	HV_{OUT} 31	38	HV_{OUT} 9
17	HV_{OUT} 32	39	HV_{OUT} 10
18	Data Out	40	HVout 11
19	N/C	41	HVout 12
20	N/C	42	HVout 13
21	Polarity	43	HVout 14
22	Clock	44	HVout 15

Package Outline



top view

44-pin J-lead Package

Preliminary

32-Channel AC Plasma Display Driver

Ordering Information

Device	Package Options						
	40-Pin Ceramic DIP	40-Pin Plastic DIP	44-Pin J-Lead Ceramic Chip Carrier	44-Pin J-Lead Plastic Chip Carrier	Die	40-Pin Ceramic Dip (MIL-STD-883 Processed*)	44-Pin J-Lead Ceramic Chip Carrier (MIL-STD-883 Processed*)
HV500	HV500D	HV500P	HV500DJ	HV500PJ	HV500X	RBHV500D	RBHV500DJ

* For Hi-Rel process flows, refer to page 5-3 of the Databook.

Features

- ☐ Processed with HVCMOS® Technology
- ☐ Output voltage of up to 100V
- ☐ CMOS push-pull output buffers
- ☐ Low-power level shifting
- ☐ Source/sink current minimum of 15mA
- ☐ Shift register speed 8MHz
- ☐ CMOS compatible inputs
- ☐ Output clamp diodes to V_{PP} and GND
- ☐ Direct replacement for the SN75500 and SN55500 series devices
- ☐ 44-lead plastic and ceramic surface mount packages available
- ☐ Hi-Rel processing available

Absolute Maximum Ratings

Supply voltage, V_{DD}[1]		-0.3V to +15V
Supply voltage, V_{PP}[1]		-0.3V to +100V
Logic input levels[1]		-0.3V to V_{DD} + 0.3V
Ground currrent[2]		1.2A[3]
Continuous total power dissipation[4]	Ceramic	1850mW
	Plastic	1200mW
Operating temperature range	Commerical	-40°C to +85°C
	Military	-55°C to 125°C
Storage temperature range		-65°C to +150°C

Notes:
1. All voltages are referenced to GND.
2. Duty cycle is limited by the total power dissipated in the package.
3. Consult factory for availability of 8.0A ground current version.
4. For operation above 25°C case temperature, derate linearly to 70°C at 15mW/°C.

General Description

The HV500 is a monolithic low-voltage logic to high-voltage output 32-channel driver for AC plasma flat panel displays. It is manufactured using the HVCMOS process, providing the high output voltages and currents possible with DMOS structures and the low power dissipation of CMOS logic.

The HV500 is comprised of an 8-stage DMOS shift register, four groups of eight high-voltage output buffers, and logic to select which group of outputs will reflect the status of the data in the shift register and strobe functions. When the strobe input is high, all outputs are held low independent of any other logic input. When strobe is brought low, the group of outputs selected by the state of the select inputs reflects the data in the shift register, and all non-selected outputs are held low.

The high-voltage output buffers have level shifters which dissipate no DC power. These level shifters also control the rise and fall times of the outputs which have been optimized to lower system noise without compromising the current source and sink capability of the output buffers. Additionally, each output has low V_{fwd} clamp diodes to V_{PP} and GND.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Max	Units	Conditions
I_{DD}	V_{DD} quiescent supply current			1	mA	
I_{PP}	V_{PP} quiescent supply current			1	mA	HV_{out} H or L
I_{IH}	High-level input current			1	µA	$V_{IN} = V_{DD}$
I_{IL}	Low-level input current			-1	µA	$V_{IN} = V_{SS}$
V_{OH}	High-level output voltage	HV outputs	94		V	I_{OH} = -1mA[1]
			90		V	I_{OH} = -15mA[1]
		Serial out	9		V	I_{OH} = -100µA[2]
V_{OL}	Low-level output voltage	HV outputs		2	V	I_{OL} = 1mA
				5	V	I_{OL} = 15mA
		Serial out		1	V	I_{OL} = 100µA[2]
V_{OK}	High voltage output			2.5	V	I_{OK} = 20mA[3]
	Clamp voltage			-2.5	V	I_{OK} = -20mA[3]

Notes:
1. V_{PP} = 100V
2. V_{DD} = 10.8V
3. V_{PP} = 0V

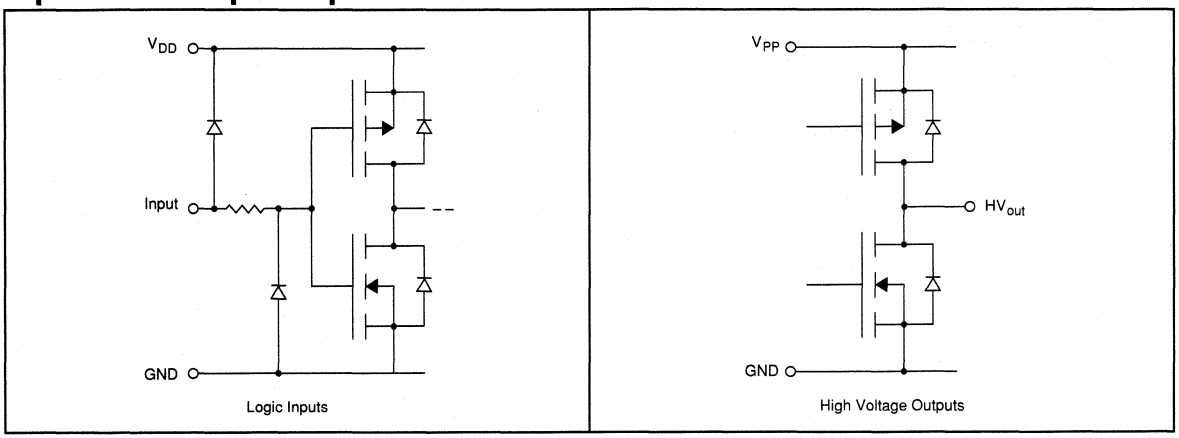
AC Characteristics (V_{DD} = 12V, V_{PP} = 100V, T_C = 25°C)

Symbol	Parameter		Min	Max	Units	Conditions
f_{MAX}	Maximum clock frequency			8	MHz	
t_W	Clock pulse width high or low		62		ns	
t_{DHL}	Delay time strobe to HV_{out} high to low		250		ns	C_L = 30pF
t_{DLH}	Delay time strobe to HV_{out} low to high		250		ns	
t_{SU}	Set-up time	Data in to clock ↑	20		ns	
		Select before strobe ↓	50		ns	
t_H	Hold time	Data after clock ↑	50		ns	
		Strobe high after clock ↑	50		ns	
		Select after strobe ↑	50		ns	
t_R	Rise time low to high HV_{out}			300	ns	C_L = 30pF
t_F	Fall time high to low HV_{out}			200	ns	C_L = 30pF

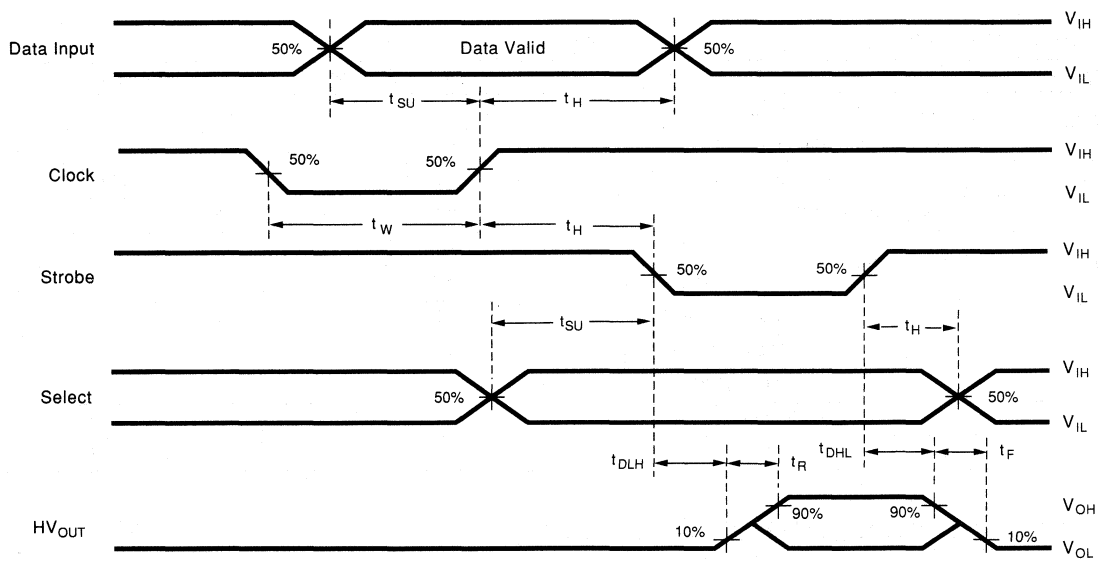
Recommended Operating Conditions

Symbol	Parameter		Min	Max	Units
V_{DD}	Logic supply voltage		10.8	13.2	V
V_{PP}	High voltage supply		0	100	V
V_{IH}	High-level input voltage		0.75 V_{DD}	V_{DD}	V
V_{IL}	Low-level input voltage		GND	0.25 V_{DD}	V
T_A	Operating free-air temperature	Commercial	-40	+85	°C
		Military Hi-Rel (RB)	-55	+125	°C

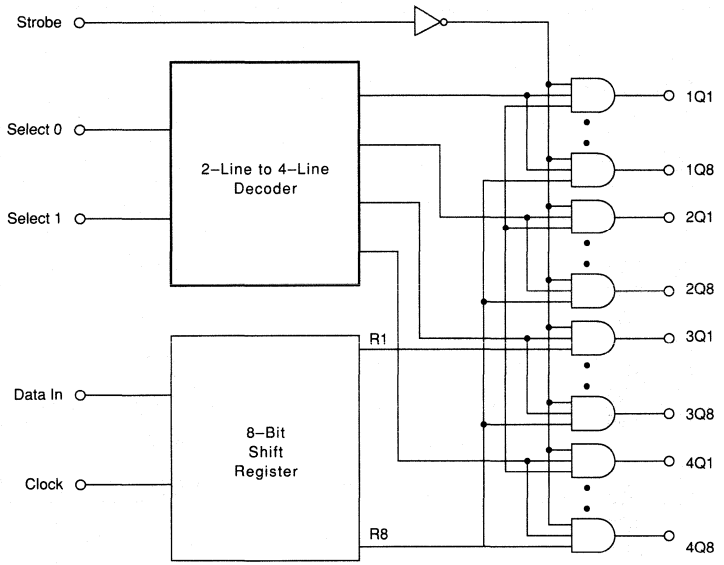
Input and Output Equivalent Circuits



Switching Waveforms



Functional Block Diagram



Function Table

Function	Inputs					Internal Levels			HV Outputs			
			Select			Shift Register						
	Data	Clk	S1	S0	Strb	R1	R2	R3...R8	1Q1...1Q8	2Q1...2Q8	3Q1...3Q8	4Q1...4Q8
Load	H	≠	X	X	H	L	R1n	R2nºR7n	LºL	LºL	LºL	LºL
	L	≠	X	X	H	H	R1n	R2nºR7n	LºL	LºL	LºL	LºL
Strobe	X	X	X	X	H	R1n	R2n	R3nºR8n	LºL	LºL	LºL	LºL
	X	H	L	L	L	R1n	R2n	R3nºR8n	R1ºR8	LºL	LºL	LºL
	X	H	L	H	L	R1n	R2n	R3nºR8n	LºL	R1ºR8	LºL	LºL
	X	H	H	L	L	R1n	R2n	R3nºR8n	LºL	LºL	R1ºR8	LºL
	X	H	H	H	L	R1n	R2n	R3nºR8n	LºL	LºL	LºL	R1ºR8

Notes:
H = high level, L = low level, X = irrelevant, ↑ = low-to-high transition.
R1ºR8 = levels currently at internal outputs of shift registers one through eight, respectively.
R1nºR8n = levels at shift-register outputs R1 through R8, respectively, before the most recent ≠ transition of the clock.

Pin Configurations

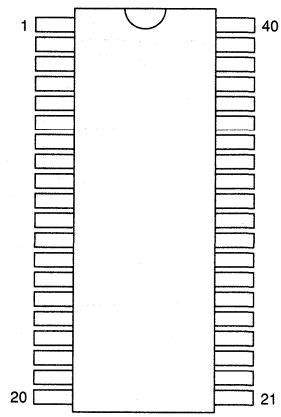
40-Pin Dual-In-Line

Pin	Function	Pin	Function
1	Select 0	21	V_{PP}
2	Data In	22	3Q8
3	Clock	23	3Q7
4	1Q1	24	3Q6
5	1Q2	25	3Q5
6	1Q3	26	3Q4
7	1Q4	27	3Q3
8	1Q5	28	3Q2
9	1Q6	29	3Q1
10	1Q7	30	4Q8
11	1Q8	31	4Q7
12	2Q1	32	4Q6
13	2Q2	33	4Q5
14	2Q3	34	4Q4
15	2Q4	35	4Q3
16	2Q5	36	4Q2
17	2Q6	37	4Q1
18	2Q7	38	Strobe
19	2Q8	39	Select 1
20	GND	40	V_{DD}

44 Pin J-Lead

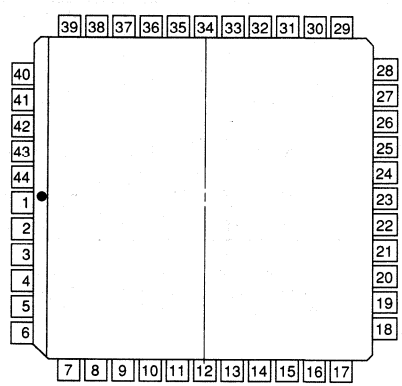
Pin	Function	Pin	Function
1	N/C	23	N/C
2	Select 0	24	V_{PP}
3	Data In	25	3Q8
4	Clock	26	3Q7
5	N/C	27	3Q6
6	1Q1	28	3Q5
7	1Q2	29	3Q4
8	1Q3	30	3Q3
9	1Q4	31	3Q2
10	1Q5	32	3Q1
11	1Q6	33	4Q8
12	1Q7	34	4Q7
13	1Q8	35	4Q6
14	2Q1	36	4Q5
15	2Q2	37	4Q4
16	2Q3	38	4Q3
17	2Q4	39	4Q2
18	2Q5	40	4Q1
19	2Q6	41	N/C
20	2Q7	42	Strobe
21	2Q8	43	Select 1
22	GND	44	V_{DD}

Package Outlines



top view

40-pin DIP



top view

44-pin J-lead Package

Preliminary

32-Channel AC Plasma Display Driver

Ordering Information

Device	Package Options						
	40-Pin Ceramic DIP	40-Pin Plastic DIP	44-Pin J-Lead Ceramic Chip Carrier	44-Pin J-Lead Plastic Chip Carrier	Die	40-Pin Ceramic Dip (MIL-STD-883 Processed*)	44-Pin J-Lead Ceramic Chip Carrier (MIL-STD-883 Processed*)
HV501	HV501D	HV501P	HV501DJ	HV501PJ	HV501X	RBHV501D	RBHV501DJ

* For Hi-Rel process flows, refer to page 5-3 of the Databook.

Features

- ☐ Processed with HVCMOS® Technology
- ☐ Output voltage of up to 100V
- ☐ DMOS push-pull output buffers
- ☐ Low-power level shifting
- ☐ Source/sink current minimum of 15mA
- ☐ Shift register speed 8MHz
- ☐ CMOS compatible inputs
- ☐ Output clamp diodes to V_{PP} and GND
- ☐ Direct replacement for the SN75501 and SN55501 series devices
- ☐ 44-lead plastic and ceramic surface mount packages available
- ☐ Hi-Rel processing available

Absolute Maximum Ratings

Supply voltage, V_{DD}[1]		-0.3V to +15V
Supply voltage, V_{PP}[1]		-0.3V to +100V
Logic input levels[1]		-0.3V to V_{DD} + 0.3V
Ground currrent[2]		1.5A[3]
Continuous total power dissipation[4]	Ceramic	1850mW
	Plastic	1200mW
Operating temperature range	Commerical	-40°C to +85°C
	Military	-55°C to 125°C
Storage temperature range		-65°C to +150°C

Notes:
1. All voltages are referenced to GND.
2. Duty cycle is limited by the total power dissipated in the package.
3. Consult factory for availability of 8.0A ground current version.
4. For operation above 25°C case temperature, derate linearly to 70°C at 15mW/°C.

General Description

The HV501 is a 32-channel low-voltage serial to high-voltage parallel converter designed for use in matrix-addressable display applications. It is manufactured with the HVCMOS technology for enhanced ruggedness and performance. This device is a direct replacement for the SN75501 family of devices.

These devices are comprised of a 32-bit shift register with a serial data out, strobe and sustain control logic, and level shifters with high-voltage DMOS output buffers. When the strobe and sustain outputs are held high the outputs are held high. Data can then be clocked into the shift register without changing the state of the outputs. When the strobe input is brought low with the sustain input remaining high, the outputs will change state to reflect the status of the data in each output's corresponding shift register bit. A logic "1" in the shift register will cause the corresponding output to pull up to V_{PP}, and a logic "0" will cause the output to pull to GND. The sustain input is used to bring all the outputs low. When the sustain input is low, all outputs are low, independent of any other control input.

The high-voltage output buffers have low power level shifters which dissipate no DC power. These level shifters also control the rise and fall times of the outputs which have been optimized to lower system noise without compromising the current source and sink capability of the output buffers. Additionally, each output has low V_{fwd} clamp diodes to V_{PP} and GND.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Max	Units	Conditions
I_{DD}	V_{DD} quiescent supply current			10	µA	
I_{PP}	V_{PP} quiescent supply current			10	µA	HV_{out} H or L
I_{IH}	High-level input current			1	µA	$V_{IN} = V_{DD}$
I_{IL}	Low-level input current			-1	µA	$V_{IN} = V_{SS}$
V_{OH}	High-level output voltage	HV outputs	94		V	I_{OH} = -1mA[1]
			90		V	I_{OH} = -15mA[1]
		Data out	9		V	I_{OH} = -100µA[2]
V_{OL}	Low-level output voltage	HV outputs		2	V	I_{OL} = 1mA
				5	V	I_{OL} = 15mA
		Data out		1	V	I_{OL} = 100µA[2]
V_{OK}	High voltage output			2.5	V	I_{OK} = 20mA[3]
	Clamp voltage			-2.5	V	I_{OK} = -20mA[3]

Notes:
1. V_{PP} = 100V
2. V_{DD} = 10.8V
3. V_{PP} = 0V

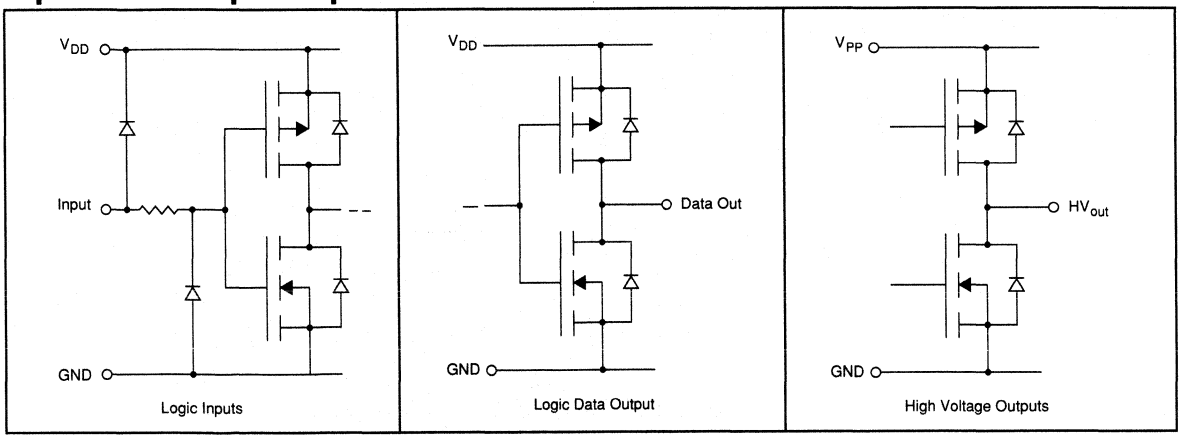
AC Characteristics (V_{DD} = 12V, V_{PP} = 80V)

Symbol	Parameter		Min	Max	Units	Conditions
f_{MAX}	Maximum clock frequency			8	MHz	
t_W	Clock pulse width high or low		62		ns	
t_{SU}	Data input set-up time before CLK		20		ns	
t_H	Data input hold time after CLK		50		ns	
t_{DHL}	Delay time High to low Level outputs	Strobe to HV_{OUT}		250	ns	C_L = 30pF
		Sustain to HV_{OUT}		250	ns	C_L = 30pF
		Serial out		147	ns	C_L = 30pF
t_{DLH}	Delay time Low to high Level outputs	Strobe to HV_{OUT}		450	ns	C_L = 30pF
		Sustain to HV_{OUT}		450	ns	C_L = 30pF
		Serial out		147	ns	C_L = 30pF
t_R	Rise time low to high HV_{OUT}			300	ns	C_L = 30pF
t_F	Fall time high to low HV_{OUT}			200	ns	C_L = 30pF

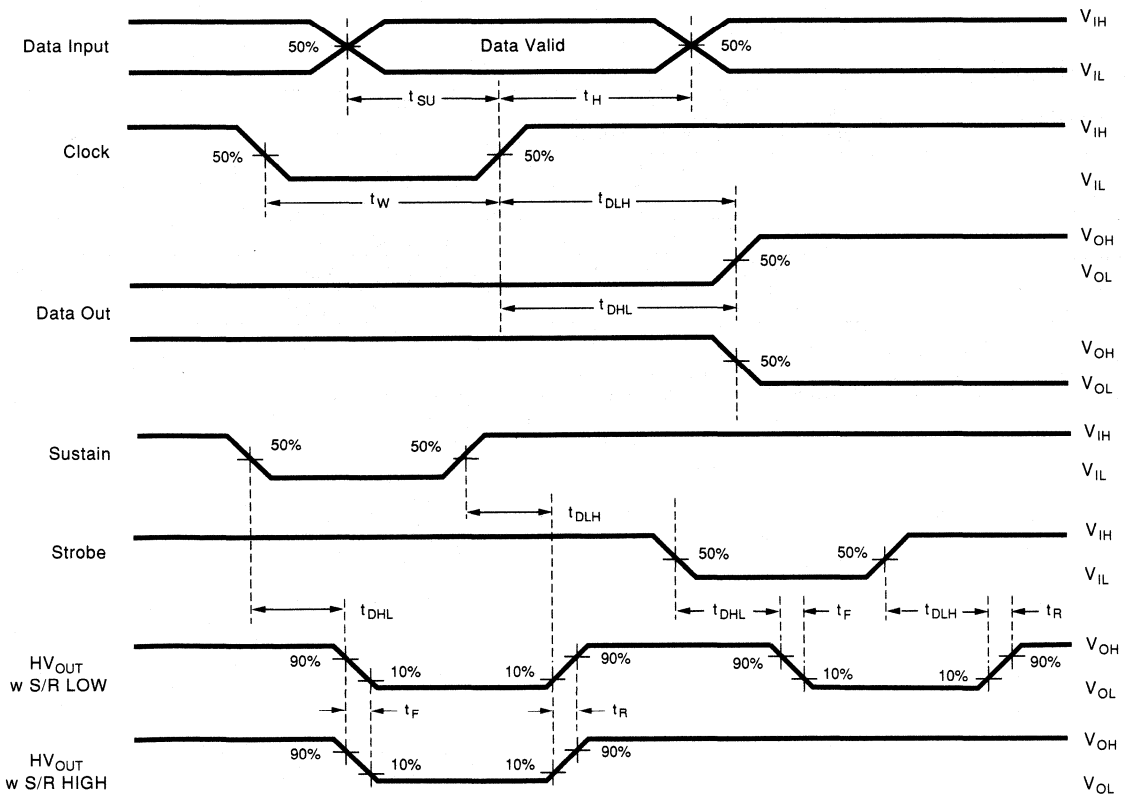
Recommended Operating Conditions

Symbol	Parameter		Min	Max	Units
V_{DD}	Logic supply voltage		10.8	13.2	V
V_{PP}	High voltage supply		8	100	V
V_{IH}	High-level input voltage		0.75 V_{DD}	V_{DD}	V
V_{IL}	Low-level input voltage		GND	0.25 V_{DD}	V
T_A	Operating free-air temperature	Commercial	-40	+85	°C
		Military Hi-Rel (RB)	-55	+125	°C

Input and Output Equivalent Circuits



Switching Waveforms



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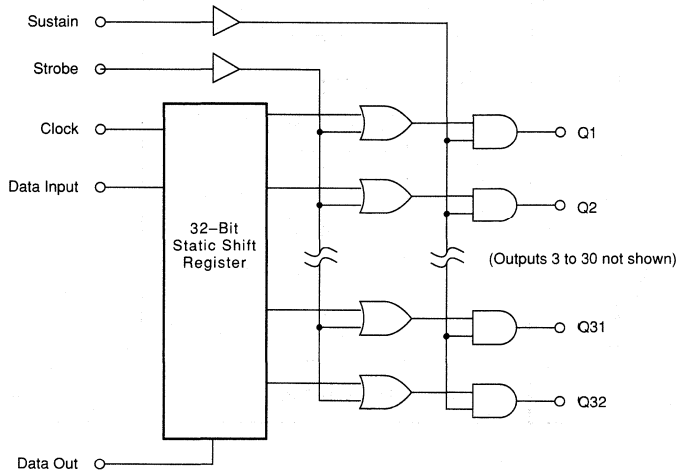
Functional Block Diagram



Function Table

Function	Inputs				Shift Register			HV Outputs		
	Data	Clock	Strobe	Sustain	R1	R2	R3...R32	1	2	3...32
Load	H	↑	H	H	H	R1n	R2n...R31n	H	H	H...H
	L	↑	H	H	L	R1n	R2n...R31n	H	H	H...H
Strobe	X	X	H	H	R1n	R2n	R3n...R32n	H	H	H...H
	X	H	L	H	R1n	R2n	R3n...R32n	R1	R2	R3...R32
Sustain	X	X	X	L	R1n	R2n	R3n...R32n	L	L	L...L

Notes:
H = high level, L = low level, X = irrelevant, ↑ = low-to-high transition.
R1...R32 = levels currently at internal outputs of shift registers one through 32, respectively.
R1n...R32n = levels at shift-register outputs R1 through R32, respectively, before the most recent ↑ transition of the clock input.

Pin Configurations

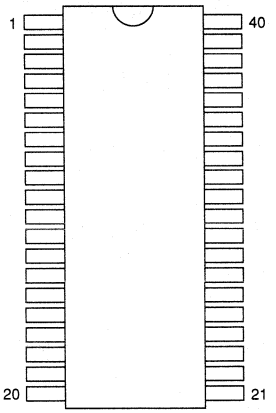
40-Pin Dual-In-Line

Pin	Function	Pin	Function
1	Clock	21	V_{PP}
2	Sustain	22	HV_{OUT} 17
3	Strobe	23	HV_{OUT} 18
4	HV_{OUT} 1	24	HV_{OUT} 19
5	HV_{OUT} 2	25	HV_{OUT} 20
6	HV_{OUT} 3	26	HV_{OUT} 21
7	HV_{OUT} 4	27	HV_{OUT} 22
8	HV_{OUT} 5	28	HV_{OUT} 23
9	HV_{OUT} 6	29	HV_{OUT} 24
10	HV_{OUT} 7	30	HV_{OUT} 25
11	HV_{OUT} 8	31	HV_{OUT} 26
12	HV_{OUT} 9	32	HV_{OUT} 27
13	HV_{OUT} 10	33	HV_{OUT} 28
14	HV_{OUT} 11	34	HV_{OUT} 29
15	HV_{OUT} 12	35	HV_{OUT} 30
16	HV_{OUT} 13	36	HV_{OUT} 31
17	HV_{OUT} 14	37	HV_{OUT} 32
18	HV_{OUT} 15	38	Data Out
19	HV_{OUT} 16	39	Data In
20	GND	40	V_{DD}

44 Pin J-Lead Package

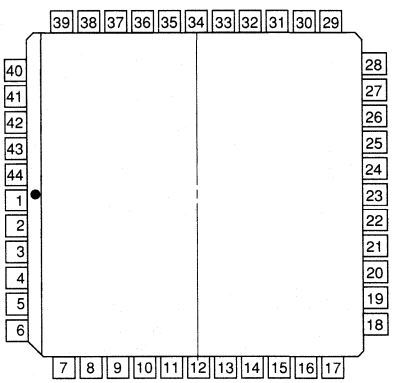
Pin	Function	Pin	Function
1	N/C	23	N/C
2	Clock	24	V_{PP}
3	Sustain	25	HV_{OUT} 17
4	Strobe	26	HV_{OUT} 18
5	N/C	27	HV_{OUT} 19
6	HV_{OUT} 1	28	HV_{OUT} 20
7	HV_{OUT} 2	29	HV_{OUT} 21
8	HV_{OUT} 3	30	HV_{OUT} 22
9	HV_{OUT} 4	31	HV_{OUT} 23
10	HV_{OUT} 5	32	HV_{OUT} 24
11	HV_{OUT} 6	33	HV_{OUT} 25
12	HV_{OUT} 7	34	HV_{OUT} 26
13	HV_{OUT} 8	35	HV_{OUT} 27
14	HV_{OUT} 9	36	HV_{OUT} 28
15	HV_{OUT} 10	37	HV_{OUT} 29
16	HV_{OUT} 11	38	HV_{OUT} 30
17	HV_{OUT} 12	39	HV_{OUT} 31
18	HV_{OUT} 13	40	HV_{OUT} 32
19	HV_{OUT} 14	41	N/C
20	HV_{OUT} 15	42	Data Out
21	HV_{OUT} 16	43	Data In
22	GND	44	V_{DD}

Package Outlines



top view

40-pin DIP



top view

44-pin J-lead Package

32-Channel Vacuum-Fluorescent Display Driver

Ordering Information

Device	Package Options	
	40 Pin Dual-In-Line	44 Pin J-lead
HV518	HV518P	HV518PJ

Features

- ☐ 32 output lines
- ☐ 90V output swing
- ☐ Active pull-down
- ☐ Latches on all outputs
- ☐ Up to 6MHz @ V_{DD} = 5V
- ☐ -40°C to +85°C operation

General Description

The HV518 is designed for vacuum fluorescent or DC plasma applications, where it can serve as a segment, digit or matrix display driver. Each device has 32 outputs, 32 latches and a 32 bit cascadable shift register.

Serial data enters the shift register on the LOW-to-HIGH transition of the clock input. With latch enable (LE) HIGH, parallel data is transferred to the output buffers through a 32-bit latch. When LE is low the data is stoped in the latch. When STROBE is LOW, all outputs are enabled; if STROBE is HIGH, all outputs are LOW.

Absolute Maximum Ratings

Supply voltage, V_{DD} [1]		-0.5V to +6.0V
Supply voltage, V_{PP} [1]		-0.5V to +90V
Logic input levels		-0.5V to V_{DD} +0.5V
Continuous total power dissipation [2,3]	Plastic	1200mW
Operating temperature range		-40°C to +85°C
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm(1/16 inch) from case for 10 seconds		260°C

Notes:

1. All voltages referenced to GND.
2. Duty cycle is limited by the total power dissipated in the package.
3. For operation above 25°C ambient, derate linearly at 13.2mW/°C for the dual-in-line package and 13.6mW/°C for the flat package.

Electrical Characteristics

(over recommended ranges of operating free-air temperature and V_{DD}. Unless otherwise noted, V_{PP} = 80V)

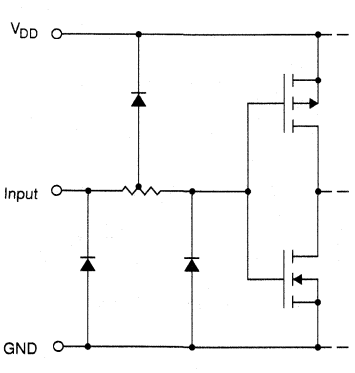
Symbol	Parameter		Min	Typ	Max	Units	Conditions
I_{DD}	Supply current				10	mA	V_{DD} = 5V, f_{CH} = 6.0 MHz
I_{PP}	Supply current				12	mA	Output high, T_A = -40°C
				7	10	mA	Output high, T_A = 0 to +85°C
					500	µA	Outputs low
V_{OH}	High-level output voltage	HVoutput	70.0			V	I_{OH}= -25mA
		Serial output	4.5	4.9	5	V	V_{DD} = 5V, I_{OH} = -20µA
V_{OL}	Low-level output	HVoutput			5	V	I_{OL}= 50µA
		Serial output		0.06	0.8	V	I_{OL} =20µA
I_{IH}	High-level logic input current			0.1	1	µA	V_{IH} = V_{DD}
I_{IL}	Low-level logic input current			-0.1	-1	µA	V_{IL} = 0V

Note: The total number of ON outputs times the duty cycle must not exceed the allowable package power disspation.

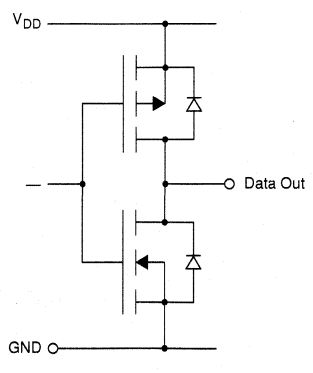
Switching Characteristics (V_{PP} = 80V, C_L = 50 pF, T_A = 25°C, unless otherwise noted)

Symbol	Parameter			Min	Max	Unit	Conditions
t_d	Delay time, Clock to data output		V_{DD} = 4.5V		600	ns	CL =15 pF See Figure 4
t_{DHL}	Delay time, high-to-low-level,	from latch enable	V_{DD} = 4.5V		1.5	µs	See Figure 5
	HVoutput	from strobe			1		See Figure 6
t_{DLH}	Delay time, low-to-high-level	from latch enable	V_{DD} = 4.5V		1.5	µs	See Figure 5
	HVoutput	from strobe			1		See Figure 6
t_{THL}	Transition time, high-to-low-level, HVoutput		V_{DD} = 4.5V		3	µs	See Figure 6
t_{TLH}	Transition time, low-to-high-level, HVoutput		V_{DD} = 4.5V		2.5	µs	See Figure 6

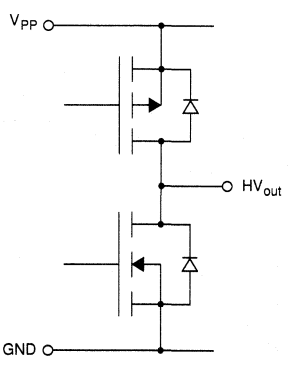
Input and Output Equivalent Circuits



Logic Inputs



Logic Data Output



High Voltage Outputs

Recommended Operating Conditions (T_A = 25°C, unless otherwise noted)

Symbol	Parameter		Min	Max	Units
V_{DD}	Logic voltage supply		4.5	5.5	V
V_{PP}	High voltage supply		8	80	V
V_{IH}	High-level input voltage (See Fig.1.)	V_{DD} = 4.5V	3.5		V
V_{IL}	Low-level input voltage (See Fig. 1.)	V_{DD} = 4.5V		1	V
I_{OH}	High-level output current		-25		mA
I_{OL}	Low-level output current			50	µA
f_{CLK}	Clock frequency (see Figure 2)	V_{DD} = 4.5V		6.0	MHz
$t_{w(CKH)}$	Pulse duration , clock high	V_{DD} = 4.5V	100		ns
$t_{w(CKL)}$	Pulse duration , clock low	V_{DD} = 4.5V	100		ns
t_{su}	Setup time, data before clock	V_{DD} = 4.5V	75		ns
t_h	Hold time, data after clock	V_{DD} = 4.5V	75		ns
T_A	Operating free-air temperature		-40	85	°C

Note:
Power-up sequence should be the following:
1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

Parameter Measurement Information

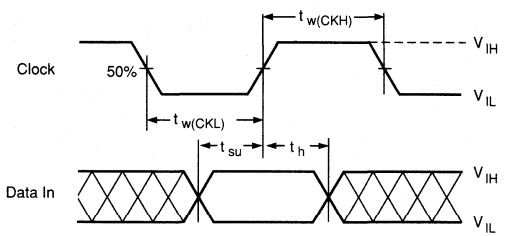


Figure 3. Input Timing Voltage Waveforms

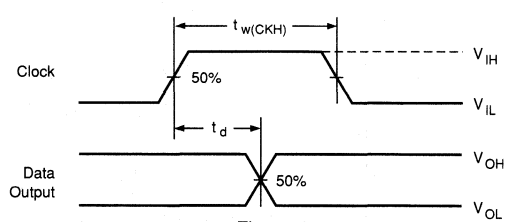


Figure 4

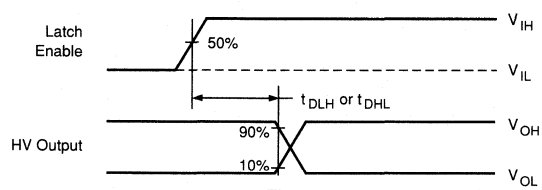


Figure 5

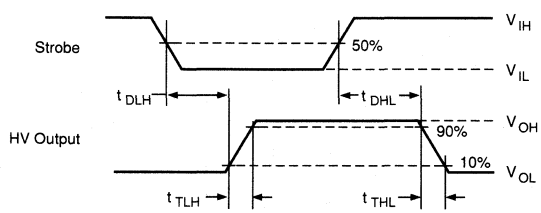
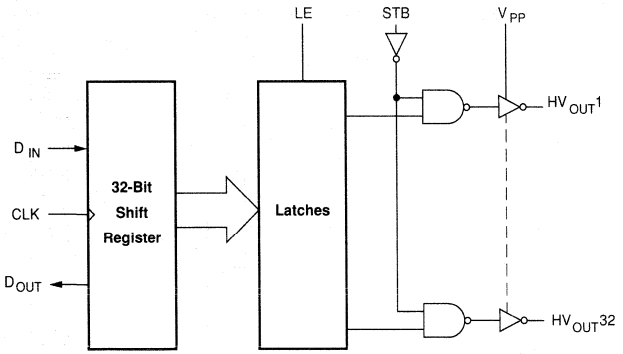


Figure 6. Switching-Time Voltage Waveforms

Note: For testing purposes, all input pulses have maximum rise and fall times of 30 nsec.

Logic Diagram



Truth Tables

Input

Data In	CLK	Data Out
H	↑	H
L	↑	L
X	No Change	*

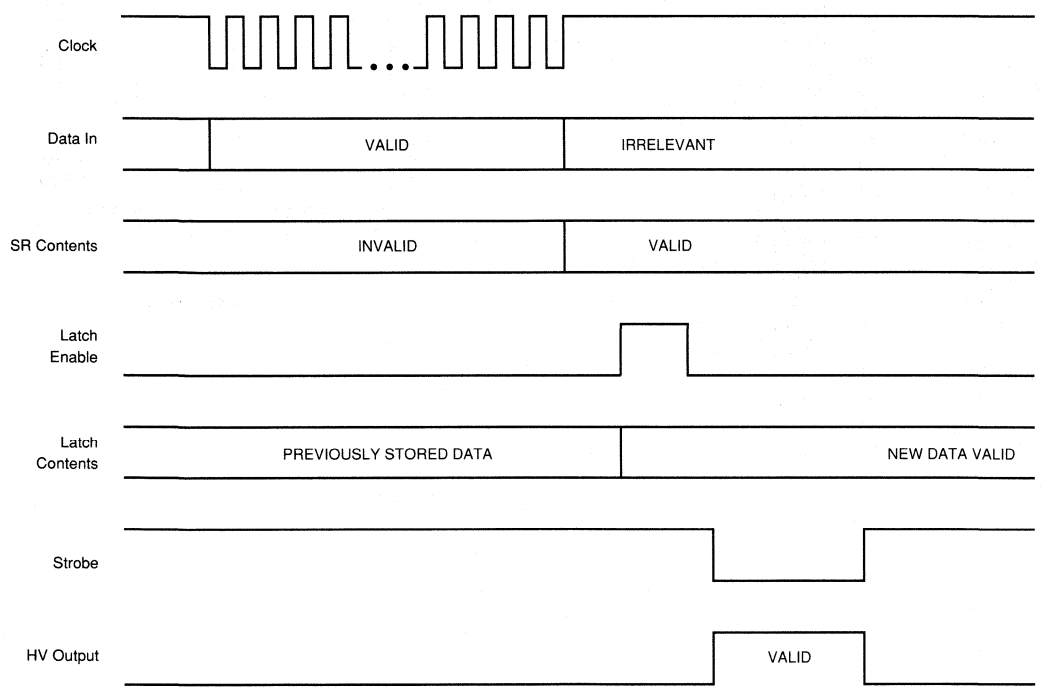
* Previous state

Output

Data In	LE	STB	HV Outputs
X	X	H	All Low
H	H	L	High
L	H	L	Low
X	L	L	*

* Previous state

Typical Operating Sequence



Pin Configurations

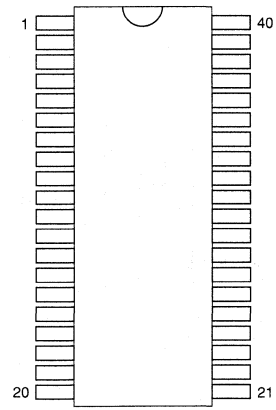
40 Pin Dual-In-Line Package

Pin	Function	Pin	Function
1	V_{PP}	21	Clock
2	Serial Out	22	LE
3	HV_{OUT} 32	23	HV_{OUT} 16
4	HV_{OUT} 31	24	HV_{OUT} 15
5	HV_{OUT} 30	25	HV_{OUT} 14
6	HV_{OUT} 29	26	HV_{OUT} 13
7	HV_{OUT} 28	27	HV_{OUT} 12
8	HV_{OUT} 27	28	HV_{OUT} 11
9	HV_{OUT} 26	29	HV_{OUT} 10
10	HV_{OUT} 25	30	HV_{OUT} 9
11	HV_{OUT} 24	31	HV_{OUT} 8
12	HV_{OUT} 23	32	HV_{OUT} 7
13	HV_{OUT} 22	33	HV_{OUT} 6
14	HV_{OUT} 21	34	HV_{OUT} 5
15	HV_{OUT} 20	35	HV_{OUT} 4
16	HV_{OUT} 19	36	HV_{OUT} 3
17	HV_{OUT} 18	37	HV_{OUT} 2
18	HV_{OUT} 17	38	HV_{OUT} 1
19	Strobe	39	Data In
20	GND	40	V_{DD}

44 Pin J-Lead Package

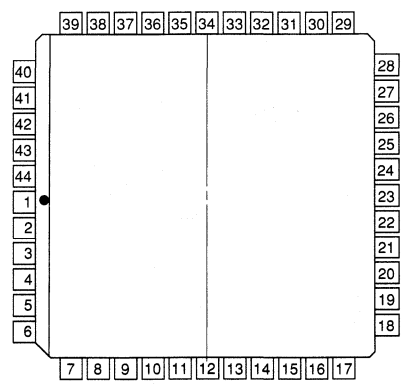
Pin	Function	Pin	Function
1	V_{PP}	23	Clock
2	Serial Out	24	LE
3	HV_{OUT} 32	25	HV_{OUT} 16
4	HV_{OUT} 31	26	HV_{OUT} 15
5	HV_{OUT} 30	27	HV_{OUT} 14
6	NC	28	NC
7	HV_{OUT} 29	29	NC
8	HV_{OUT} 28	30	HV_{OUT} 13
9	HV_{OUT} 27	31	HV_{OUT} 12
10	HV_{OUT} 26	32	HV_{OUT} 11
11	HV_{OUT} 25	33	HV_{OUT} 10
12	HV_{OUT} 24	34	HV_{OUT} 9
13	HV_{OUT} 23	35	HV_{OUT} 8
14	HV_{OUT} 22	36	HV_{OUT} 7
15	HV_{OUT} 21	37	HV_{OUT} 6
16	HV_{OUT} 20	38	HV_{OUT} 5
17	HV_{OUT} 19	39	HV_{OUT} 4
18	NC	40	HV_{OUT} 3
19	HV_{OUT} 18	41	HV_{OUT} 2
20	HV_{OUT} 17	42	HV_{OUT} 1
21	Strobe	43	Data In
22	GND	44	V_{DD}

Package Outline



top view

40-pin DIP



top view

44-pin J-lead Package

Preliminary

32-Channel ±40V Liquid Crystal Display Row Driver

Ordering Information

Device	Package Options			
	44-J lead Quad Plastic Chip Carrier	44 -J Lead Quad Ceramic Chip Carrier	44-Lead Quad Plastic Gullwing	Die
HV6008	HV6008PJ	HV6008DJ	HV6008PG	HV6008X

Features

- ☐ Symmetrical ± 40V output swing
- ☐ Active return to GND
- ☐ 15mA peak source/sink/GND current per channel
- ☐ +5V control logic
- ☐ Special shift register with clear
- ☐ Phase shift control
- ☐ Output enable
- ☐ Data out enable
- ☐ 1MHz shift register
- ☐ Surface mount package available

Absolute Maximum Ratings

Supply voltage, V_{DD1}[1]	-6
Supply voltage, V_{DD2}[1]	+6
Supply voltage, V_{PP}[1,2]	+42V
Supply voltage, V_{NN}[1,2]	-42V
Logic input levels	V_{DD1} - 0.3V to V_{DD2} + 0.3V
Ground currrent[2]	700mA
Continuous total power dissipation[3]	1W
Operating temperature range	0°C to 70°C
Storage temperature range	-65°C to +150°C

Notes:
1. All voltages are referenced to GND.
2. Duty cycle is limited by the total power dissipated in the package.
3. For operation above 25°C ambient, derate linearly to 85°C at 15mW/°C.

General Description

The HV60 is a 32-channel liquid crystal display driver with 3-state DMOS outputs. Each output can be set to +40V, -40V, or GND. A symmetric waveform can be applied to a capacitive load using the phase shift feature of the HV60.

The HV60 consists of a 32-bit shift register with Clear, Enable, and Phase Shift logic, and 32 high voltage output buffers. With the Enable pin held low, all outputs are placed in the return to zero (GND) state. When Enable is high, each output reflects the data in its shift register bit. All outputs with a logic "0" in their shift register will be in the return to zero state. Outputs with a logic "1" in their shift register will reflect the state of the phase shift pin. These outputs will be switched to V_{PP} when phase shift is high and V_{NN} when phase shift is logic "0".

Additional functions provided are Shift Register Clear and Data Out. All bits of the shift register are changed to logic "0" when Clear is pulled low. With Clear at a logic "1", normal shift register operation proceeds. The data output reflects the status of the 32nd shift register stage.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Typ	Max	Units	Conditions
$I_{DD1,2}$	V_{DD} supply current	V_{DD1}			500	µA	V_I = 4V, V_{DD1} = -6V
		V_{DD2}					V_I = 4V, V_{DD2} = +6V
V_{IH}	Logic input high		+2		V_{DD2}	V	V_{DD1} = -4.5V,
V_{IL}	Logic input low		V_{DD1}		-2	V	V_{DD2} = +4.5V
V_{OH}	Logic output high		+2			V	V_{DD1} = -4.5V V_{DD2} = +4.5V
V_{OL}	Logic output low				-2	V	I_{OH} = -15µA I_{OL} = 250µA
I_{IH}	High-level logic input current				+3	µA	$V_I = V_{DD}$, $V_{DD1,2}$ = max
I_{IL}	Low-level logic input current				-50	µA	V_I = 0V, $V_{DD1,2}$ = max
I_{PP}	High voltage supply current				+1	mA	Static, no load
I_{NN}	High voltage supply current				-1	mA	Static, no load
V_{OH}	Output voltage high		+39			V	V_{PP}, V_{NN} = ±40 I_{output} = 0.0
V_{CL}	Output voltage clamp		-20		+20	mV	
V_{OL}	Output voltage low				-39	V	
Z_{OH}	Output switch impedence high			1000		Ω	V_{PP}, V_{NN} = ±40 I_O = ±15mA
Z_{CL}	Output switch impedance clamp			500			
Z_{OL}	Output switch impedance low			700			
I_O	DC output current	Output H or L			5	mA	1 output only
		Data out H or L			150	µA	

AC Characteristics

Symbol	Parameter	Min	Typ	Max	Units	Conditions
t_{WH}	Width of high clock phase		TBD			
t_{WL}	Width of low clock phase		TBD			
t_{SU}	Data set-up time before clock rises		TBD			
t_H	Data hold time after clock rises	0			ns	
	Phase shift duty cycle		50		%	

Recommended Operating Conditions

Symbol	Parameter	Min	Typ	Max	Units
V_{DD1}	Logic supply voltage	-4		-6	V
V_{DD2}	Logic supply voltage	+4		+6	V
V_{PP}	High voltage supply	+10		+40	V
V_{NN}	High voltage supply	-10		-40	V
V_{IH}	High-level input voltage	+2V		V_{DD2}	V
V_{IL}	Low-level input voltage	-2V		V_{DD1}	V
$I_{O\ Pk.}$	Peak output current (any state)			±80	mA
T_A	Operating free-air temperature	0		+70	°C
f_{DIN}	Input data rate			1	MHz
f_{PS}	Phase shift rate			1	MHz

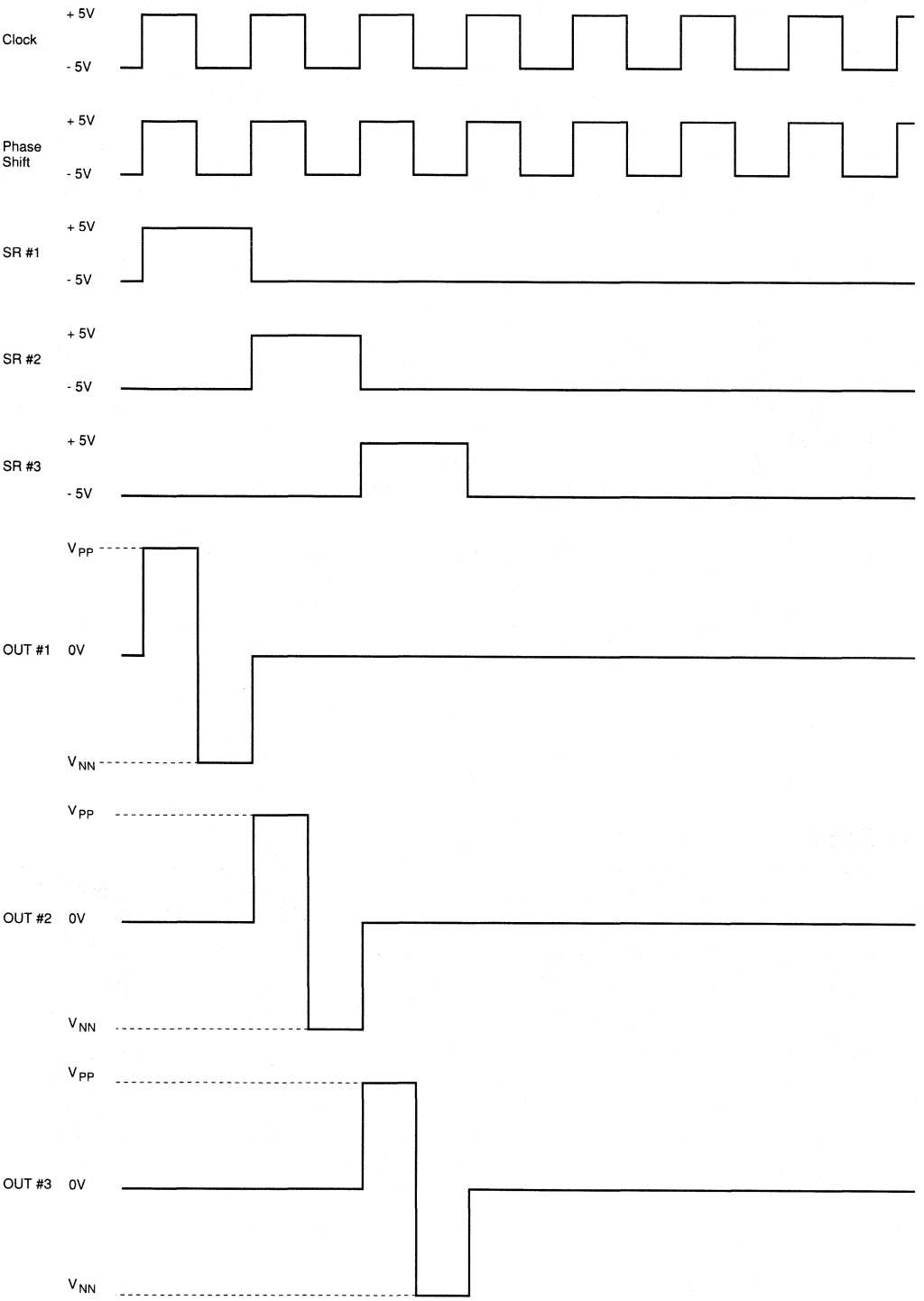
Note:

Power-up sequence should be the following:

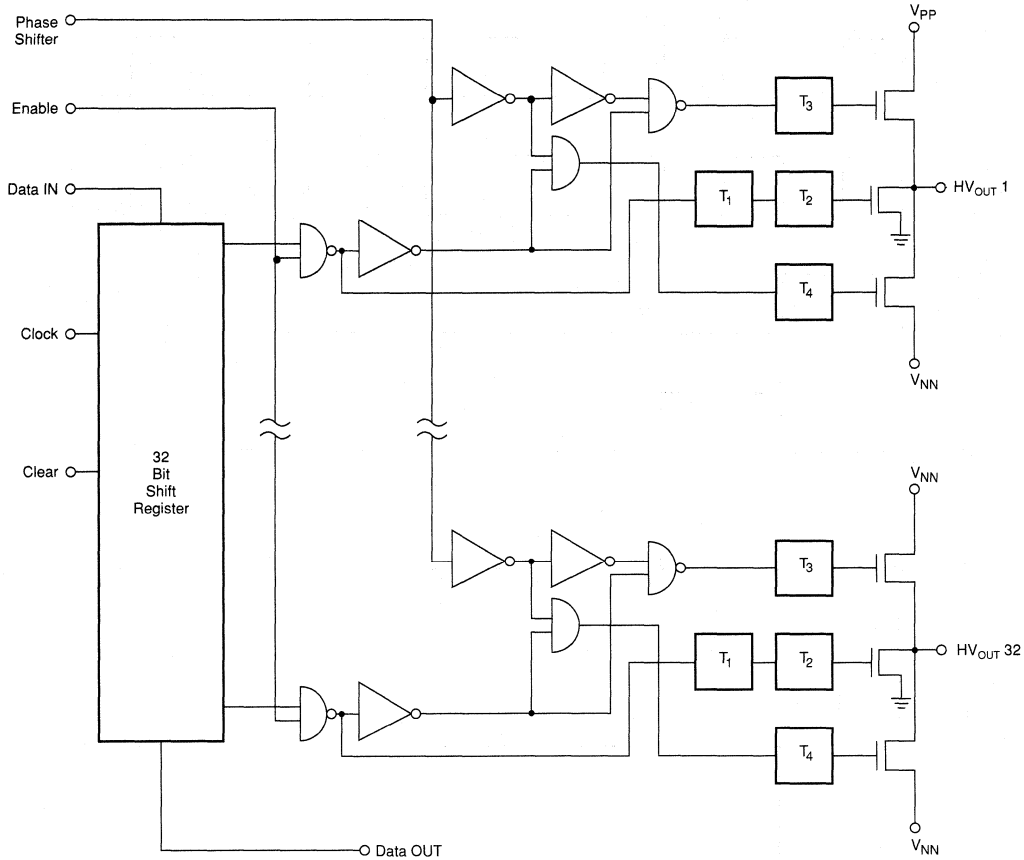
1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

Switching Waveform



Functional Block Diagram



Function Table

Function	Inputs						Outputs	
	Data In	CLK	CLR	Enable	Phase Shift	Shift Reg 1 2...32	HV Outputs 1 2...32	Data Out
CLR Reg	X	X	L	X	X	ALL L	ALL GND	H
All output GND	X	X	X	L	X	* *...*	ALL GND	*
Load S/R	H or L	↑	H	L	X	H or L *...*	ALL GND	*
Output State	X	H or L	H	H	X	L L...L	GND GND...GND	*
					H	H H...H	V_{PP} V_{PP}...V_{PP}	*
					L	L L...L	V_{NN} V_{NN}...V_{NN}	*

Notes:
X = Don't care
* = Dependent on previous stage's state before the last CLK
↑ = Low to high transition
H = High level
L = Low level

Pin Configurations

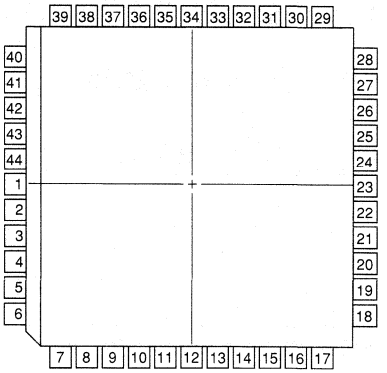
44-Pin J-Lead

Pin	Function	Pin	Function
1	HV_{OUT} 16	23	V_{DD} 1 = (-5)
2	HV_{OUT} 15	24	Enable
3	HV_{OUT} 14	25	V_{DD} 2 = (+5)
4	HV_{OUT} 13	26	GND
5	HV_{OUT} 12	27	D_{OUT}
6	HV_{OUT} 11	28	HV_{OUT} 32
7	HV_{OUT} 10	29	HV_{OUT} 31
8	+ 40V	30	HV_{OUT} 30
9	HV_{OUT} 9	31	HV_{OUT} 29
10	HV_{OUT} 8	32	HV_{OUT} 28
11	HV_{OUT} 7	33	HV_{OUT} 27
12	HV_{OUT} 6	34	HV_{OUT} 26
13	HV_{OUT} 5	35	HV_{OUT} 25
14	HV_{OUT} 4	36	HV_{OUT} 24
15	HV_{OUT} 3	37	- 40V
16	HV_{OUT} 2	38	HV_{OUT} 23
17	HV_{OUT} 1	39	HV_{OUT} 22
18	Data In	40	HV_{OUT} 21
19	GND	41	HV_{OUT} 20
20	Phase Shift	42	HV_{OUT} 19
21	$\overline{\text{Clock}}$	43	HV_{OUT} 18
22	$\overline{\text{Clear}}$	44	HV_{OUT} 17

44-Pin Quad Palstic Package

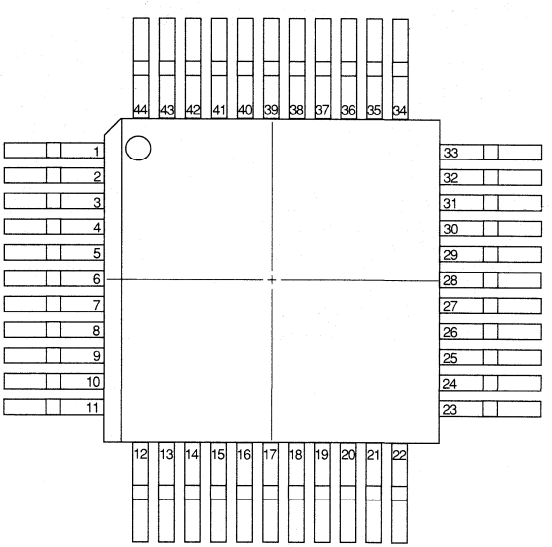
Pin	Function	Pin	Function
1	HV_{OUT} 21	23	Data In
2	HV_{OUT} 20	24	GND
3	HV_{OUT} 19	25	$\overline{\text{Phase Shift}}$
4	HV_{OUT} 18	26	$\overline{\text{CLK}}$
5	HV_{OUT} 17	27	Clear
6	HV_{OUT} 16	28	-5V
7	HV_{OUT} 15	29	Enable
8	HV_{OUT} 14	30	+5V
9	HV_{OUT} 13	31	GND
10	HV_{OUT} 12	32	Data Out
11	HV_{OUT} 11	33	HV_{OUT} 24
12	HV_{OUT} 10	34	HV_{OUT} 25
13	V_{PP}	35	HV_{OUT} 26
14	HV_{OUT} 9	36	HV_{OUT} 27
15	HV_{OUT} 8	37	HV_{OUT} 28
16	HV_{OUT} 7	38	HV_{OUT} 29
17	HV_{OUT} 6	39	HV_{OUT} 30
18	HV_{OUT} 5	40	HV_{OUT} 31
19	HV_{OUT} 4	41	HV_{OUT} 32
20	HV_{OUT} 3	42	V_{PP}
21	HV_{OUT} 2	43	HV_{OUT} 23
22	HV_{OUT} 1	44	HV_{OUT} 22

Package Outlines



top view

44-Pin PJ and DJ Package



top view

44-pin Quad Plastic Package

Preliminary

64-Channel Military TFT ±10V Liquid Crystal Display Driver

Ordering Information

Device	Package Options		
	80-Lead Quad Ceramic Gullwing	80-Lead Quad Ceramic Gullwing (MIL-STD-883 Processed*)	Die
HV61	HV6101DG	RBHV6101DG	HV6101X

* For Hi-Rel process flows, refer to page 5-3 of the Databook.

Features

- ☐ Symmetrical + 10V output swing
- ☐ Active return to ground
- ☐ +12V control logic
- ☐ Bidirectional shift control pin
- ☐ Data out for cascading
- ☐ 8MHz clock

Absolute Maximum Ratings

Supply Voltage, V_{DD}	-0.5 to +15.0V_{DC}
Supply Voltage, V_{SS}	-0.5 to +15.0V_{DC}
Logic Input Levels	(-0.5) to (V_{DD} + 0.5)V_{DC}
Continuous Total Power Disipatation	1500mW
Operating Temperature Range	-55°C to +125°C
Storage Temperature Range	-65°C to +150°C
Die Storage Temperature Range	-65°C to +150°C

Notes:
1. All voltages are referenced to GND.
2. Duty cycle is limited by the total power dissipated in the package.

General Description

The HV61 is a 64-channel latched serial-to-parallel converter with bidirectional shifting capability and high-voltage outputs that can be switched in polarity from V_{PP} to V_{NN}. It is intended mainly as a driver for active-matrix liquid crystal displays in military systems.

The shift direction is controlled by pins SHFL and CSB. A low at CSB enables the shift function, which occurs at the low-to-high transition of the clock. A high at SHFL causes data to be shifted "right-to left" (from L_{IN} R_{OUT} toward L_{OUT} R_{IN}), and vice versa.

The 64 latches are transparent when LOAD is high, and the data is latched when load is low.

The FRAME control reverses the voltage polarity of outputs that are in the logical high state. For FRAME = high, high-level outputs will be at V_{DD} level: for FRAME = low, high-level outputs will be at V_{SS} level. Outputs at logic low will be low regardless of FRAME.

Electrical Characteristics

DC Characteristics

Notes 1 & 2

Symbol	Parameter	Min	Typ	Max	Units	Conditions
I_{DD}	V_{DD} Current	0		500	mA	V_{DD} = 12V[3]
I_{SS}	V_{SS} Current	—		-500	mA	V_{SS}= -12V[3]
I_{IH}	Input High Leakage Current	0		10	mA	VIH = 12V
I_{IL}	Input Low Leakage Current	-10		0	mA	VIL = 0V
I_{OMP}	Output Source Current	-1.0		—	mA	V_{OH} = 11.5V
I_{OHN}	Output Source Current	1.0		—	mA	V_{OH} = 11.5V
I_{OL}	Output Sink Current	1.0		—	mA	V_{OH} = 0.5V

Notes:
1. V_{DD} =12V, V_{SS}=-12V
2. Negative current indicates current flow out of the device
3. No load

Recommended Operating Conditions

Symbol	Parameter	Min	Typ	Max	Units	Conditions
V_{DD}	Supply Voltage	9	10	13.2	V	
V_{SS}	Supply Voltage	9	10	13.2	V	
V_{IH}	High-level input voltage	V_{DD}-2		V_{DD}	V	
V_{IL}	Low-level input voltage	0		2	V	

Note:

Power-up sequence should be the following:
1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

Truth Tables

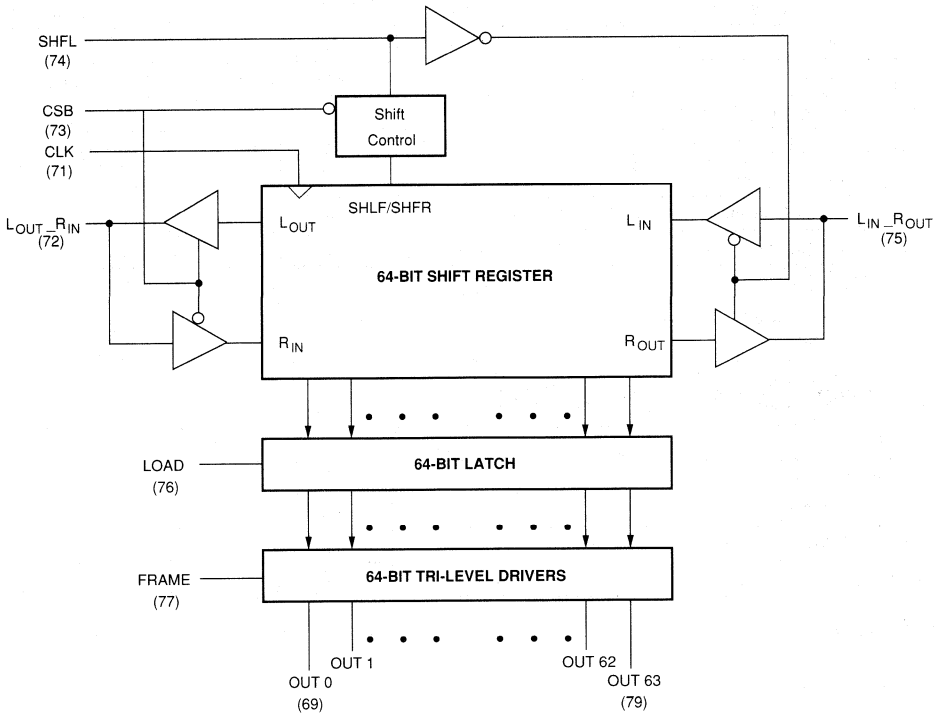
Input

CSB	SHFL	Shift Register
H	X	No Shift
L	H	Shift Left (L_{IN} R_{OUT} to L_{OUT} R_{IN})
L	L	Shift Right (L_{OUT} RI_N to L_{IN} R_{OUT})

Output

Load	FRAME	Outputs
L	X	L (Previous Data)
H	H	V_{DD} (New Data: Latch Transparent)

Functional Block Diagram

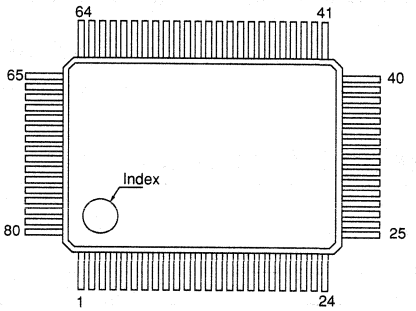


Pin Configuration

80-Gullwing Package

Pin	Function	Pin	Function
1	GND	41	Q25
2	Q61	42	Q24
3	Q60	43	V_{SS}
4	Q59	44	Q23
5	Q58	45	Q22
6	Q57	46	Q21
7	Q56	47	Q20
8	Q55	48	Q19
9	Q54	49	Q18
10	Q53	50	Q17
11	V_{SS}	51	Q16
12	Q52	52	V_{DD}
13	Q51	53	Q15
14	Q50	54	Q14
15	Q49	55	Q13
16	Q48	56	Q12
17	Q47	57	Q11
18	Q46	58	Q10
19	Q45	59	Q09
20	Q44	60	Q08
21	V_{DD}	61	Q07
22	Q43	62	Q06
23	Q42	63	Q05
24	Q41	64	V_{SS}
25	Q40	65	Q04
26	Q39	66	Q03
27	Q38	67	Q02
28	Q37	68	Q01
29	Q36	69	Q00
30	Q35	70	GND
31	Q34	71	CLK
32	GND	72	L_{OUT} R_{IN}
33	Q33	73	CSB
34	Q32	74	SHFL
35	Q31	75	L_{IN} R_{OUT}
36	Q30	76	Load
37	Q29	77	Frame
38	Q28	78	V_{DD}
39	Q27	79	Q63
40	Q26	80	Q62

Package Outline



top view

80-pin Gullwing Package

Product Objective Specification

32-Channel LCD Driver with Separate Backplane Output

Ordering Information

Device	Package Options	
	44 J-Lead Quad Plastic Chip Carrier	Dice in waffle pack
HV67	HV6706PJ	HV6706X

Features

- ☐ Processed with HVCMOS® technology
- ☐ Output voltages up to 60V
- ☐ Low power level shifting
- ☐ Source/sink current minimum 5mA
- ☐ Shift register speed 5MHz
- ☐ Latched data outputs
- ☐ Bidirectional shift register (R/L Shift)
- ☐ Backplane Output

Absolute Maximum Ratings[1]

Supply voltage, V_{DD}[2]	-0.5V to +7.0V
Output voltage, V_{PP}	V_{DD} to +80V
Logic input levels[2]	-0.5V to V_{DD} +0.5V
Ground currrent[3]	1.5A
Continuous total power dissipation[4]	1500mW
Operating temperature range	-40°C to +85°C
Storage temperature range	-65°C to +125°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds	260°C

Notes:

1. Device will survive (but operation may not be specified or guaranteed) at these extremes.
2. All voltages are referenced to V_{SS}.
3. Duty cycle is limited by the total power dissipated in the package.
4. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

General Description

The HV67 is a low-voltage serial to high-voltage parallel converter wtih push-pull outputs.This device has been designed for use as a driver for LCD displays. It can also be used in any application requiring multiple output high-voltage current sourcing and sinking capabilities . The inputs are fully CMOS compatible.

The device consists of a 32-bit shift register, 32 latches, and control logic to perform the polarity select and blanking (optional) of the outputs. HVout1 is connected to the first stage of the shift register through the polarity and blanking logic. Data is shifted through the shift register on the logic low to high transition of the clock. A R/L Shift pin causes data shifting counterclockwise when grounded and clockwise when connected to V_{DD}. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register (HVout32). Operation of the shift register is not affected by the LE (latch enable), BL (blanking), or the POL (polarity) inputs. Transfer of data from the shift register to the latch occurs when the LE (latch enable) input is high. The data in the latch is stored during LE transition from high to low.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics (V_{DD} = 5V, V_{PP} = 60V, V_{SS} = GND)

Symbol	Parameter		Min	Max	Units	Conditions
I_{DD}	V_{DD} supply current			15	mA	$V_{DD} = V_{DD}$ max f_{CLK} = 5MHz
I_{PP}	High voltage supply current			0.5	mA	Outputs high
				0.5	mA	Outputs low
I_{DDQ}	Quiescent V_{DD} supply current			0.5	mA	All $V_{IN} = V_{SS}$ or V_{DD}
V_{OH}	High-level output	Q	52		V	I_O= 5mA, V_{PP} = 60V
		Data out	4.6		V	I_O= -500µA
V_{OL}	Low-level output	Q		8	V	I_O= 5mA, V_{PP} = 60V
		Data out		0.4	V	I_O= 500µA
I_{IH}	High-level logic input current			1	µA	$V_{IH} = V_{DD}$
I_{IL}	Low-level logic input current			-1	µA	V_{IL} = 0V
V_{OLBP}	Low-level output voltage, backplane			8	V	I_O = 40mA
V_{OHBP}	High-level output viltage, backplane		52		V	I_O = -40mA

AC Characteristics (V_{DD} = 5V, V_{PP} = 60V, T_C = 25°C)

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock frequency		5	MHz	
t_W	Clock width high or low	100		ns	
t_{SU}	Data set-up time before clock rises	25		ns	
t_H	Data hold time after clock rises	50		ns	
t_{ON}, t_{OFF}	Time from latch enable or POL to HV_{OUT}		500	ns	C_L = 30pF
t_{ON}, t_{OFF}	Time from POL to BP output		500	ns	C_L = 30pF
t_{DHL}	Delay time clock to data high to low		75	ns	C_L = 15pF
t_{DLH}	Delay time clock to data low to high		75	ns	C_L = 15pF
t_{DLE}	Delay time clock to LE low to high	50		ns	
t_{WLE}	Width of LE pulse	100		ns	
t_{SLE}	$\overline{LE}$ set-up time before clock rises	50		ns	

Recommended Operating Conditions

Symbol	Parameter	Min	Max	Units
V_{DD}	Logic supply voltage	4.5	5.5	V
V_{PP}	Output off voltage	35	60	V
V_{IH}	High-level input voltage	3.5	V_{DD}	V
V_{IL}	Low-level input voltage	0	0.8	V
f_{CLK}	Clock frequency		5	MHz
T_A	Operating free-air temperature	-40	+85	°C
I_{OD}	Allowable current through output diodes		200	mA

Note:

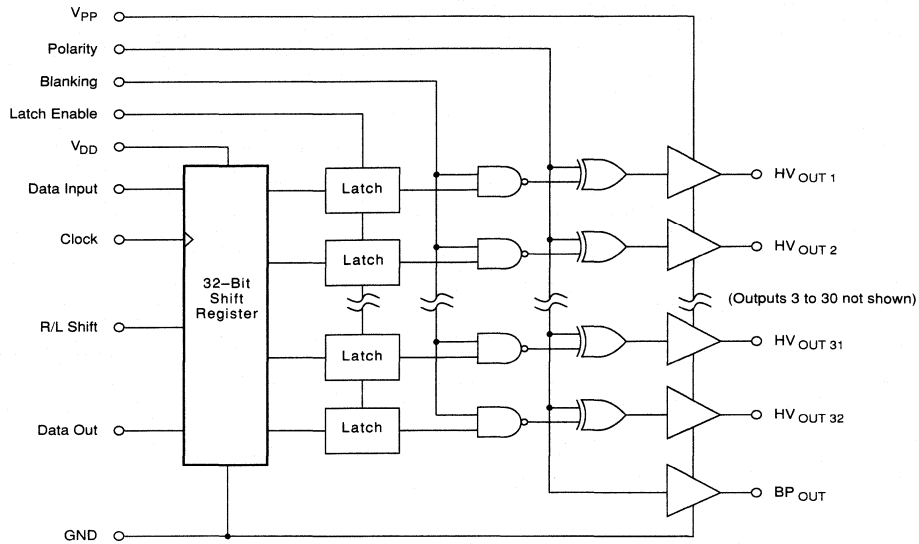
Power-up sequence should be the following:

1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

5. The V_{PP} should not drop below V_{DD} during operation.

Functional Block Diagram

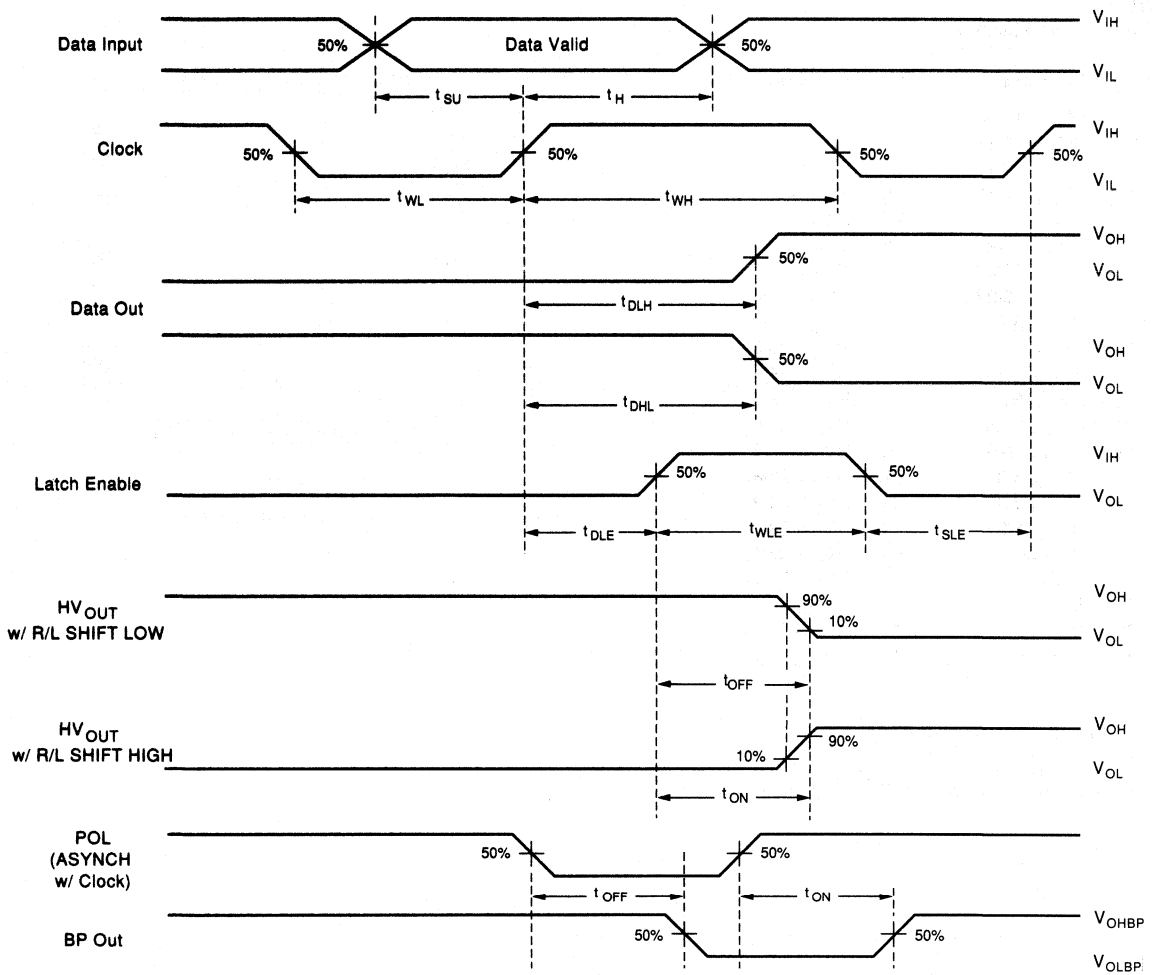


Function Table

Function	Inputs					Outputs		
	Data	CLK	LE	BL	POL	Shift Reg 1 2...32	HV Outputs 1 2...32	Data Out *
All on	X	X	X	L	L	* *...*	H H...H	*
All off	X	X	X	L	H	* *...*	L L...L	*
Invert mode	X	X	L	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Load S/R	H or L	↑	L	H	H	H or L *...*	* *...*	*
Load latches	X	H or L	↑	H	H	* *...*	* *...*	*
	X	H or L	↑	H	L	* *...*	$\overline{*}$ $\overline{*...*}$	*
Transparent latch mode	L	↑	H	H	H	L *...*	L *...*	*
	H	↑	H	H	H	H *...*	H *...*	*

Notes:
H = high level, L = low level, X = irrelevant, ↑ = low-to-high transition.
* = dependent on previous stage's state before the last CLK or last $\overline{LE}$ high,

Switching Waveforms



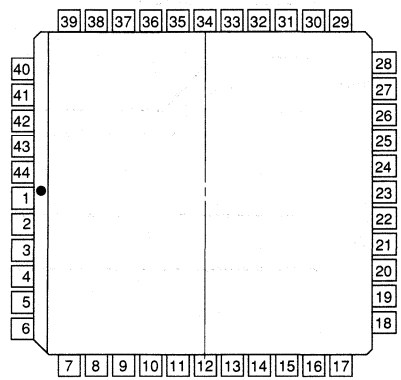
Pin Configuration

HV67
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 17/16	23	LE
2	HV_{OUT} 16/17	24	V_{DD}
3	HV_{OUT} 15/18	25	Clock
4	HV_{OUT} 14/19	26	R/L Shift
5	HV_{OUT} 13/20	27	Data In
6	HV_{OUT} 12/21	28	V_{PP}
7	HV_{OUT} 11/22	29	BP Out
8	HV_{OUT} 10/23	30	HV_{OUT} 32/1
9	HV_{OUT} 9/24	31	HV_{OUT} 31/2
10	HV_{OUT} 8/25	32	HV_{OUT} 30/3
11	HV_{OUT} 7/26	33	HV_{OUT} 29/4
12	HV_{OUT} 6/27	34	HV_{OUT} 28/5
13	HV_{OUT} 5/28	35	HV_{OUT} 27/6
14	HV_{OUT} 4/29	36	HV_{OUT} 26/7
15	HV_{OUT} 3/30	37	HV_{OUT} 25/8
16	HV_{OUT} 2/31	38	HV_{OUT} 24/9
17	HV_{OUT} 1/32	39	HV_{OUT} 23/10
18	Data Out	40	HV_{OUT} 22/11
19	GND	41	HV_{OUT} 21/12
20	BL	42	HV_{OUT} 20/13
21	N/C	43	HV_{OUT} 19/14
22	POL	44	HV_{OUT} 18/15

Note:
1. Pin designation for R/L Shift = L/H
   Example: for R/L Shift = L Pin 1 is HV_{OUT} 17
   for R/L Shift = H Pin 1 is HV_{OUT} 16
2. Blanking function is optional, BL pin can be left open when not used.

Package Outline



top view

44-pin J-lead Package

10-Channel Serial-Input Latched Display Driver

Ordering Information

Device	Package Options				
	18-Pin Ceramic Dip	18-Pin Plastic Dip	20-Pin Small Outline Package	20-Pin Plastic Chip Carrier	18-Pin Ceramic Dip (MIL-STD-883 Processed*)
HV6810	HV6810D	HV6810P	HV6810WG	HV6810PJ	RBHV6810D

* For Hi-Rel process flows, refer to page 5-3 of the Databook.

Features

- ☐ High output voltage 80V
- ☐ High speed 5MHz @ $5V_{DD}$
- ☐ Low power $I_{BB} \leq 0.1mA$ (All high)
- ☐ Active pull down 2.5mA min
- ☐ Output source current 60mA
- ☐ Each device drives 10 lines
- ☐ High-speed serially-shifted data input
- ☐ 5V CMOS-compatible inputs
- ☐ Latches on all driver outputs
- ☐ Pin-compatible improved replacement for UCN5810A and TL4810A, TL4810B

General Description

The HV6810 is a monolithic integrated circuit designed to drive a dot matrix or segmented vacuum fluorescent display (VFD). These devices feature a serial data output to cascade additional devices for large displays.

A 10-bit data word is serially loaded into the shift register on the positive-going transition of the clock. Parallel data is transferred to the output buffers through a 10-bit D-type latch while the latch enable input is high and is latched when the latch enable is low. When the blanking input is high, all outputs are low.

Outputs are structures formed by double-diffused MOS (DMOS) transistors with output voltage ratings of 80 volts and 60 milliampere source-current capability. All inputs are compatible with CMOS levels.

Absolute Maximum Ratings[1]

Logic supply voltage, V_{DD}[2]		7.5V
Driver supply voltage, V_{BB}		90V
Output voltage		90V
Input voltage		-0.3V to V_{DD} + 0.3V
Continuous total power dissipation at 25°C free-air temperature [3]	Ceramic	1500mW
	Plastic	875mW
Operating Temperature Range	Commerical	-40 to +85°C
	Military	-55 to +125°C

Notes:
1. Over operating free-air temperature.
2. All voltages are referenced to V_{SS}.
3. For operation above 25°C free-air temperature the derating factor is 7.0mW/°C.

Electrical Characteristics

DC Characteristics (V_{DD} = 5V ±10%, V_{BB} = 60V, V_{SS} = 0, T_A = 25°C unless otherwise noted)

Symbol	Parameter		Min	Typ	Max	Units	Conditions
V_{OH}	High-level output voltage	Q outputs	57.5	58		V	I_{OH} = 25mA
		Serial output	4	4.5		V	V_{DD} = 4.5V, I_{OH} = -100µA
V_{OL}	Low-level output voltage	Q outputs		0.15	1	V	I_{OH} = 100µA, Blanking input at V_{DD}
		Serial output		0.05	0.1	V	V_{DD} = 4.5V, I_{OL} = 100µA
I_{OL}	Low-level Q output current (pull-down current)		60	80		µA	T_A = Max, V_{OL} = 0.7V
$I_{O(OFF)}$	Off-state output current			-1	-15	µA	V_O = 0, Blanking input T_A = Max at V_{DD}
I_H	High-level input current				1	µA	V_I = V_{DD}
I_{DD}	Supply current from V_{DD} (standby)			10	50	µA	All inputs at 0V, one Q output high
				10	50	µA	All inputs at 0V, all Q outputs low
I_{BB}	Supply current from V_{BB}			0.05	0.1	mA	All outputs low, all Q outputs open
				0.05	0.1	mA	All outputs high, all Q outputs open

* All typical values are at T_A = 25°C, except for I_O.

AC Characteristics (Timing requirements over recommended operating conditions)

Symbol	Parameter	Min	Typ	Max	Units	Conditions
$t_{W(CKH)}$	Pulse duration, clock high	100			ns	
$t_{W(LEH)}$	Pulse duration, latch enable high	100			ns	
$t_{SU(D)}$	Setup time, data before clock	50			ns	
$t_{H(D)}$	Setup time, data after clock	50			ns	
$t_{CKH-LEH}$	Delay time, clock to latch enable high	50			ns	
t_{pd}*	Propagation delay time, latch enable to output		0.3		µs	

* Switching characteristics, V_{BB} = 60V, T_A = 25°C.

Recommended Operating Conditions

(Note 1)

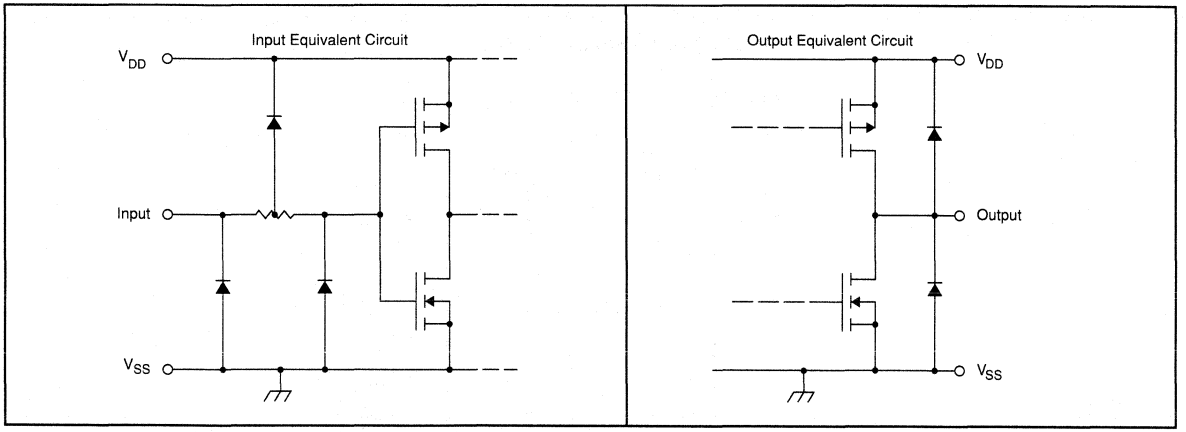
Symbol	Parameter		Min	Nom	Max	Units
V_{DD}	Supply voltage		4.5		5.5	V
V_{BB}	Supply voltage		20		80	V
V_{SS}	Supply voltage			0		V
V_{IH}	High-level input voltage (for V_{DD} = 5V)		3.5	0	5.3	V
V_{IL}	Low-level input voltage		-0.3		0.8	V
I_{OH}	Continuous high-level Q output current		-25			mA
T_A	Operating free-air temperature	Commerical	-40		+85	°C
		Military	-55		+125	

Note:
Power-up sequence should be the following:

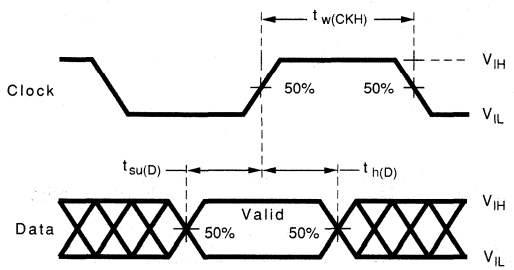
1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

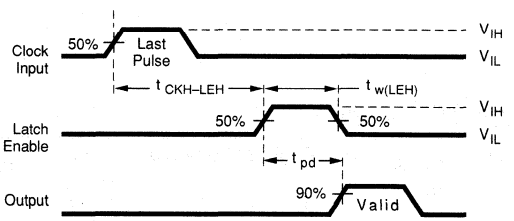
Input and Output Equivalent Circuits



Switching Waveforms

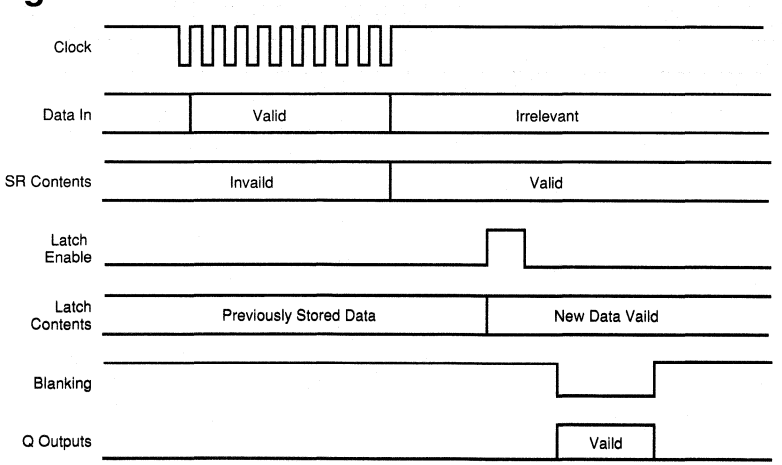


Input Timing



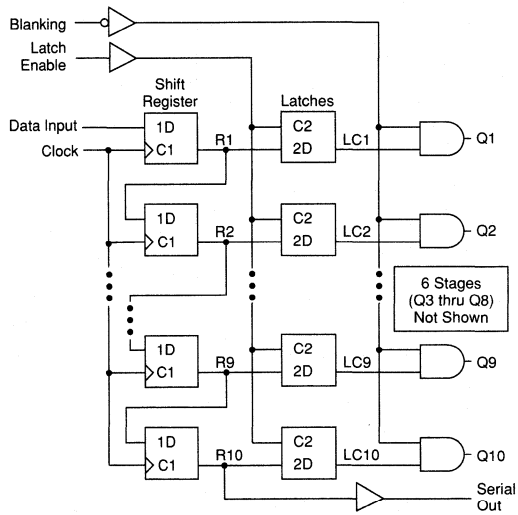
Output Switching Times

Timing Diagram



Functional Block Diagram

Logic Diagram (positive logic)



Function Table

Serial Data Input	Clock Input	Shift Register Contents I_1 I_2 I_3 ... I_{N-1} I_N	Serial Data Output	Strobe Input	Latch Contents I_1 I_2 I_3 ... I_{N-1} I_N	Blanking Input	Output Contents I_1 I_2 I_3 ... I_{N-1} I_N
H	⎍	H R_1 R_2 ... R_{N-2} R_{N-1}	R_{N-1}				
L	⎍	L R_1 R_2 ... R_{N-2} R_{N-1}	R_{N-1}				
X	⎎	R_1 R_2 R_3 ... R_{N-1} R_N	R_N				
		X X X ... X X	X	L	R_1 R_2 R_3 ... R_{N-1} R_N		
		P_1 P_2 P_3 ... P_{N-1} P_N	P_N	H	P_1 P_2 P_3 ... P_{N-1} P_N	L	P_1 P_2 P_3 ... P_{N-1} P_N
					X X X ... X X	H	L L L ... L L

L = Low logic level
H = High logic level
X = Irrelevant
P = Present state
R = Previous state

Pin Configurations

18-Pin DIP

Pin	Function	Pin	Function
1	Q8	10	Q3
2	Q7	11	Q2
3	Q6	12	Q1
4	Clock	13	Blanking
5	V_{SS}	14	Data in
6	V_{DD}	15	V_{BB}
7	LE (strobe)	16	Serial data out
8	Q5	17	Q10
9	Q4	18	Q9

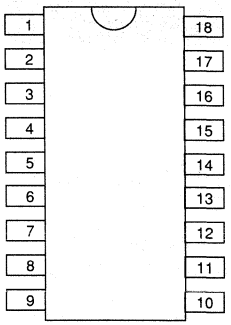
20-Pin SOW

Pin	Function	Pin	Function
1	Q8	11	Q3
2	Q7	12	Q2
3	Q6	13	Q1
4	Clock	14	Blanking
5	V_{SS}	15	Data in
6	N/C	16	V_{BB}
7	V_{DD}	17	Serial data out
8	LE (strobe)	18	N/C
9	Q5	19	Q10
10	Q4	20	Q9

20-Pin Plastic PLCC

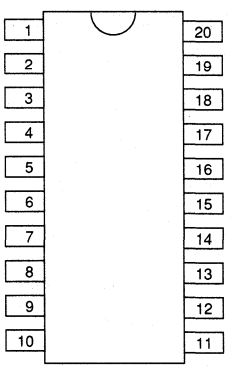
Pin	Function	Pin	Function
1	Q8	11	Q3
2	Q7	12	Q2
3	Q6	13	Q1
4	Clock	14	Blanking
5	N/C	15	Data In
6	V_{SS}	16	N/C
7	V_{DD}	17	V_{BB}
8	LE(Strobe)	18	Serial data out
9	Q5	19	Q10
10	Q4	20	Q9

Package Outlines



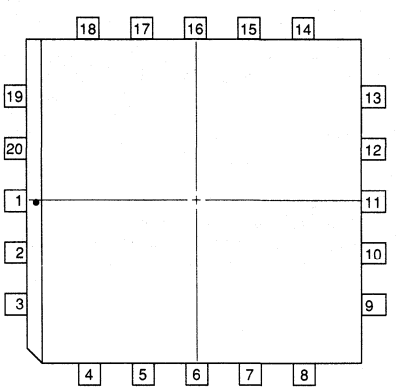
top view

18-pin DIP



top view

SOW 20



top view

20-pin PJ and PG Package

34-Channel Symmetric Row Driver

Ordering Information

Device	Package Options			
	44 J-Lead Quad Ceramic Chip Carrier	44 J-Lead Quad Plastic Chip Carrier	Die in waffle pack	44 J-Lead Quad Ceramic Chip Carrier (MIL-STD-883 Processed*)
HV7022	HV7022DJ	HV7022PJ	HV7022X	RBHV7022DJ

* For Hi-Rel process flows, refer to page 5-3 of the Databook.

Features

- ☐ Processed with HVCMOS® technology
- ☐ Symmetric row drive (reduces latent imaging in ACTFEL displays)
- ☐ Output voltages up to 230V
- ☐ Low-power level shifting
- ☐ Source/Sink current 70mA (min.)
- ☐ Shift Register Speed 4MHz
- ☐ Pin-programmable shift direction
- ☐ 44-lead plastic & ceramic surface-mount packages
- ☐ Hi-Rel processing available

General Description

The HV70 is a low-voltage serial to high-voltage parallel converter with push-pull outputs. It is especially suitable for use as a symmetric row driver in AC thin-film electroluminescent (ACTFEL) displays. The HV70 offers 34 output lines, a direction (DIR) pin to give CW or CCW shift register loading, output enable (OE), and polarity (POL) control. After DATA INPUT is entered (on the falling edge of CLOCK), a logic high will cause the output to swing to V_{PP} if POL is high, or to GND if POL is low.

Absolute Maximum Ratings

Supply voltage, V_{DD}[1]		-0.3V to +15V
Supply voltage, V_{PP}		-0.3V to +250V
Logic input levels		-0.3V to V_{DD} +0.3V
Ground currrent[2]		1.5A
Continuous total power dissipation[3]:	Ceramic	1500mW
	Plastic	1200mW
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes: 1. All voltages are referenced to GND.
2. Duty cycle is limited by the total power dissipated in the package.
3. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

Electrical Characteristics

(over recommended operating conditions of V_{DD} = 12V, V_{PP} = 230V, and T_A = 25°C unless noted)HV_{OUT}

DC Characteristics

Symbol	Parameter		Min	Max	Units	Conditions
I_{DD}	V_{DD} supply current			10	mA	f_{CLK} = 4MHz
I_{PP}	High voltage supply current			4	mA	1 Output high[1]
				100	µA	All Outputs low or High-Z
				750	µA	All Outputs low or High-Z (125°C)
I_{DDQ}	Quiescent V_{DD} supply current			100	µA	All V_{IN} = GND or V_{DD}
V_{OH}	High-level output	HV_{OUT}	195		V	I_O= -70mA (-50mA)[2]
		Data out	11		V	I_O= -500µA
V_{OL}	Low-level output	HV_{OUT}		30	V	I_O= 70mA (-50mA)[2]
		Data out		1	V	I_O= 500µA
I_{IH}	High-level logic input current			1	µA	V_{IH} = 12V
I_{IL}	Low-level logic input current			-1	µA	V_{IL} = 0V

Note:

1 The total number of ON outputs times the duty cycle must not exceed the allowable package power disspation.

2. Over miliary temperature range.

AC Characteristics (V_{DD} = 12V, T_A = 25°C)

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock frequency		4	MHz	
t_W	Pulse duration clock high or low	125		ns	
t_{SUD}	Data set-up time before falling clock	100		ns	
t_{HD}	Data hold time after falling clock	100		ns	
t_{SUC}	Setup time clock low before V_{PP}↑ or GND↓	300		ns	
t_{SUE}	Setup time enable high before V_{PP}↑ or GND↓	300		ns	
t_{SUP}	Setup time polarity high or low before V_{PP}↑ or GND↓	300		ns	
t_{HC}	Hold time clock high after V_{PP}↑ or GND↓	500		ns	
t_{HE}	Hold time enable high after V_{PP}↑ or GND↓	300		ns	
t_{HP}	Hold time polarity high or low after V_{PP}↑ or GND↓	300		ns	
t_{DHL}	Delay time high to low level output from clock		150	ns	C_L = 10pF
t_{DLH}	Delay time low to high level output from clock		200	ns	C_L = 10pF
t_{THL}	Transition time high to low level serial output		200	ns	C_L = 15pF
t_{TLH}	Transition time low to high level serial output		100	ns	C_L = 15pF
t_{ONH}	High level turn-on time Q outputs from enable		500	ns	I_O = -50 mA, V_{OH} =195V R_L = 2 kΩ to 95V
t_{ONL}	Low level turn-on time Q outputs from enable		500	ns	I_O = 50 mA, V_{OH} =130V R_L = 2 kΩ to 30V
t_{OFFH}	High level turn-off time Q outputs from enable		1000	ns	I_O = -50 mA, V_{OH} =195V R_L = 2 kΩ to 95V
t_{OFFL}	Low level turn-off time Q outputs from enable		500	ns	I_O = 50 mA, V_{OH} =130V R_L = 2 kΩ to 30V
dv/dt	Slew rate, V_{PP} or GND		45	V/µs	With one active output driving a 4.7 nF load to V_{PP} or GND

Recommended Operating Conditions

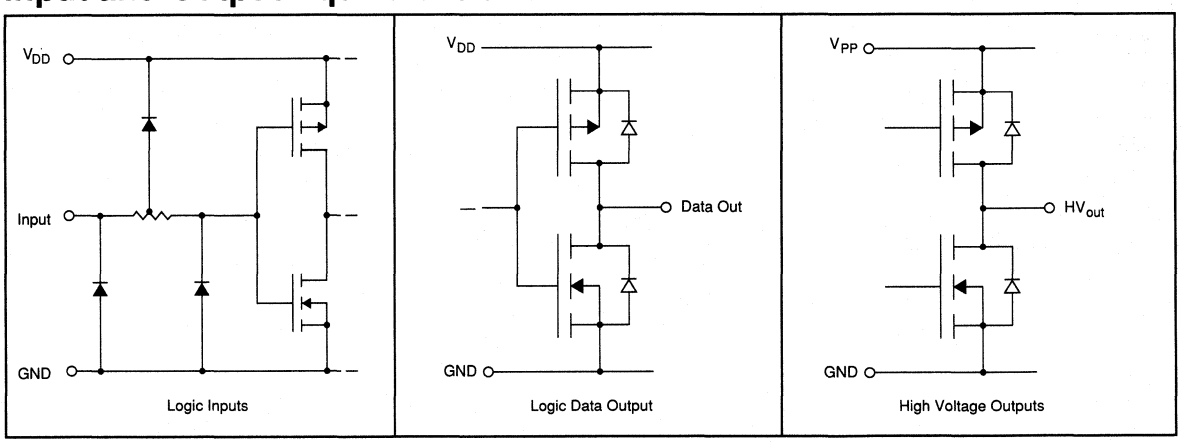
Symbol	Parameter		Min	Max	Units
V_{DD}	Logic supply voltage		10.8	13.2	V
V_{PP}	High voltage supply			230	V
V_{IH}	High-level input voltage	V_{DD} = 10.8V	8.1		V
		V_{DD} = 13.2V	9.9		
V_{IL}	Low-level input voltage	V_{DD} = 10.8V		2.7	V
		V_{DD} = 13.2V		3.3	
f_{CLK}	Clock frequency			4	MHz
T_A	Operating free-air temperature	Commercial	0	+70	°C
		Military Hi-Rel (RB)	-55	+125	°C
I_{OD}	Allowable pulsed current through output diode			300	mA

Note:
Power-up sequence should be the following:

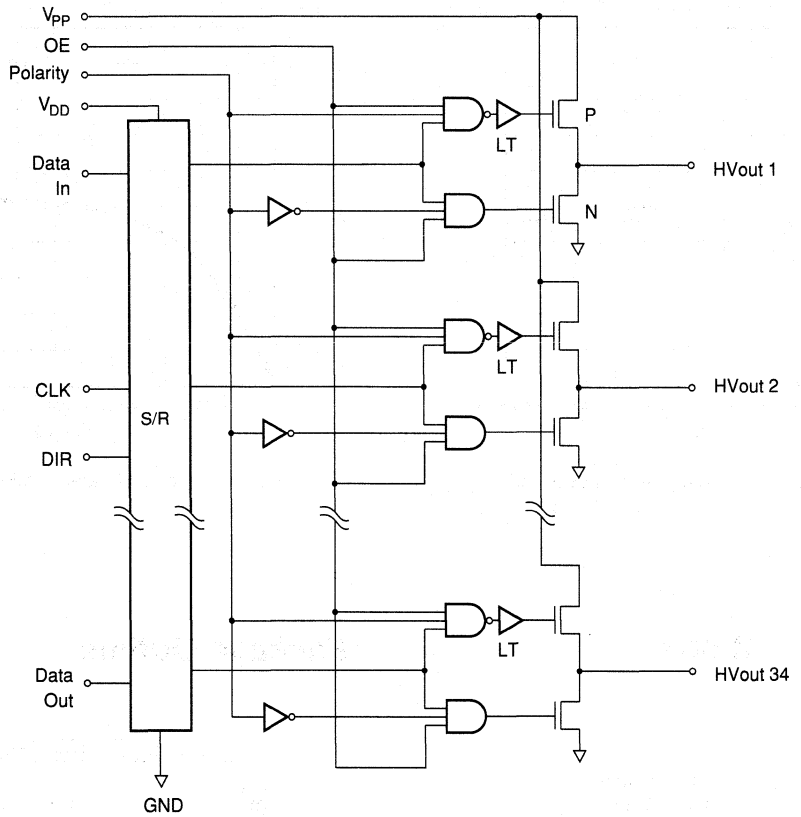
1. Connect ground.
2. Apply VDD.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply VPP.

Power-down sequence should be the reverse of the above.

Input and Output Equivalent Circuits



Functional Block Diagram



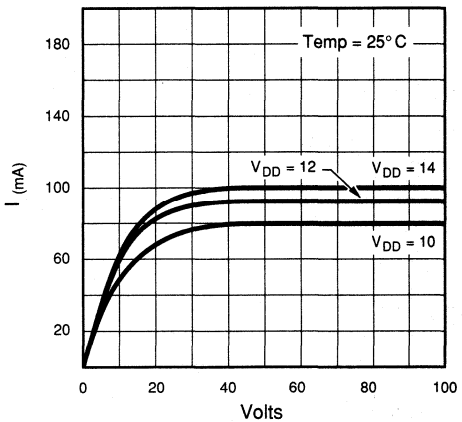
LT = Level Translator

Function Table

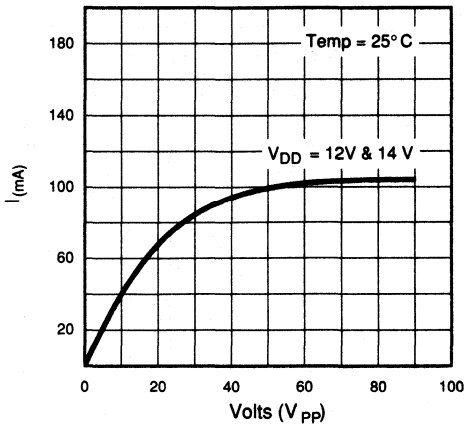
I/O Relations	Inputs					Outputs		
	CLK	DIR	Data	POL	OE	Shift Reg	HV Outputs	Data Out
O/P HIGH	X	X	H	H	H	*	H	
O/P OFF	X	X	L	H	H	*	HIGH-Z	*
O/P LOW	X	X	H	L	H	*	L	*
O/P OFF	X	X	L	L	H	*	HIGH-Z	*
O/P OFF	X	X	X	X	L	*	All O/P HIGH-Z	*
Load S/R, set DIR	↓	L	X	X	X	$Q_n \rightarrow Q_{n+1}$	*	Q_{34}
	↓	H	X	X	X	$Q_n \rightarrow Q_{n-1}$	*	Q_1
	No ↓	X	X	X	X	*	No Change	No Change

Notes:
H = logic high level, L = logic low level, X = irrelevant, Ø = high-to-low transition,
$Q_1 = HV_{out}$ 1, $Q_n = HV_{out}$ (n), etc.
* = dependent on previous state and whether an O/P or S/R command occured.

HV_{OUT} Characteristics



Output N-channel Characteristics through FET



Output P-channel Characteristics through FET

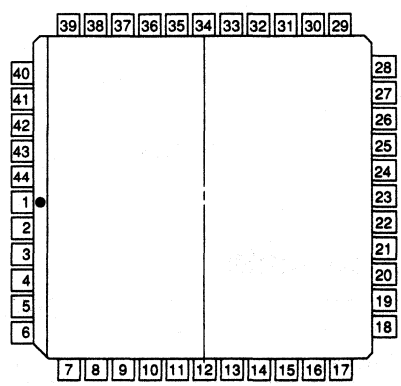
Pin Configurations

HV70
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 18/17	23	DIR
2	HV_{OUT} 17/18	24	V_{DD}
3	HV_{OUT} 16/19	25	Polarity
4	HV_{OUT} 15/20	26	Data In
5	HV_{OUT} 14/21	27	V_{PP}
6	HV_{OUT} 13/22	28	N/C
7	HV_{OUT} 12/23	29	HV_{OUT} 34/1
8	HV_{OUT} 11/24	30	HV_{OUT} 33/2
9	HV_{OUT} 10/25	31	HV_{OUT} 32/3
10	HV_{OUT} 9/26	32	HV_{OUT} 31/4
11	HV_{OUT} 8 /27	33	HV_{OUT} 30/5
12	HV_{OUT} 7/28	34	HV_{OUT} 29/6
13	HV_{OUT} 6/29	35	HV_{OUT} 28/7
14	HV_{OUT} 5/30	36	HV_{OUT} 27/8
15	HV_{OUT} 4/31	37	HV_{OUT} 26/9
16	HV_{OUT} 3/32	38	HV_{OUT} 25/10
17	HV_{OUT} 2/33	39	HV_{OUT} 24/11
18	HV_{OUT} 1/34	40	HV_{OUT} 23/12
19	Data Out	41	HV_{OUT} 22/13
20	Output Enable	42	HV_{OUT} 21/14
21	Clock	43	HV_{OUT} 20/15
22	GND	44	HV_{OUT} 19/16

Note:
Pin designation for DIR L/H
Example: For DIR = L, pin 1 is HV_{OUT} 18
For DIR H, pin 1 is HV_{OUT} 17

Package Outline



top view

44-pin J-lead Package

Product Objective Specification

40-Channel Symmetric Row Driver

Ordering Information

Device	Package Options			
	64-Lead 3-Sided Ceramic Gullwing	64-Lead 3-Sided Plastic Gullwing	Die in waffle pack	64-Lead 3-Sided Ceramic Gullwing (MIL-STD-883 Processed*)
HV7225	HV7225DJ	HV7225PJ	HV7225X	RBHV7225DJ

* For Hi-Rel process flows, refer to page 5-3 of the Databook.

Features

- ☐ Processed with HVCMOS® technology
- ☐ Symmetric row drive (reduces latent imaging in ACTFEL displays)
- ☐ Output voltages up to 250V
- ☐ Low-power level shifting
- ☐ Source/Sink current 100mA (max.)
- ☐ Shift Register Speed 4MHz
- ☐ Pin-programmable shift direction
- ☐ Hi-Rel processing available

General Description

The HV72 is a low-voltage serial to high-voltage parallel converter with push-pull outputs. It is especially suitable for use as a symmetric row driver in AC thin-film electroluminescent (ACTFEL) displays. The HV72 offers 40 output lines, a direction (DIR) pin to give CW or CCW shift register loading, output enable (OE), and polarity (POL) control. After DATA INPUT is entered (on the falling edge of CLOCK), a logic high will cause the output to swing to V_{PP} if POL is high, or to GND if POL is low.

Absolute Maximum Ratings

Supply voltage, V_{DD}[1]		-0.3V to +6V
Supply voltage, V_{PP}		-0.3V to +250V
Logic input levels		-0.3V to V_{DD} +0.3V
Ground currrent[2]		1.5A
Continuous total power dissipation[3]:	Ceramic	1500mW
	Plastic	1200mW
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. All voltages are referenced to GND.
2. Duty cycle is limited by the total power dissipated in the package.
3. For operation above 25°C ambient, derate linearly to 72°C at 12mW/°C.

Electrical Characteristics

(over recommended operating conditions of V_{DD} = 5V, V_{PP} = 230V, and T_A = 25°C unless noted)

DC Characteristics

Symbol	Parameter		Min	Max	Units	Conditions
I_{DD}	V_{DD} supply current			10	mA	f_{CLK} = 4MHz
I_{PP}	High voltage supply current			4	mA	1 Output high[1]
				100	µA	All Outputs low or High-Z
				750	µA	All Outputs low or High-Z (125°C)
I_{DDQ}	Quiescent V_{DD} supply current			100	µA	All V_{IN} = GND or V_{DD}
V_{OH}	High-level output	HV_{OUT}	200		V	I_O= -70mA
		Data out	11		V	I_O= -500µA
V_{OL}	Low-level output	HV_{OUT}		30	V	I_O= 70mA
		Data out		1	V	I_O= 500µA
I_{IH}	High-level logic input current			1	µA	V_{IH} = 12V
I_{IL}	Low-level logic input current			-1	µA	V_{IL} = 0V

Note1 The total number of ON outputs times the duty cycle must not exceed the allowable package power disspation.

AC Characteristics (V_{DD} = 12V, T_A = 25°C)

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock frequency		4	MHz	
t_W	Pulse duration clock high or low	125		ns	
t_{SUD}	Data set-up time before falling clock	100		ns	
t_{HD}	Data hold time after falling clock	100		ns	
t_{SUC}	Setup time clock low before V_{PP}↑ or GND↓	300		ns	
t_{SUE}	Setup time enable high before V_{PP}↑ or GND↓	300		ns	
t_{SUP}	Setup time polarity high or low before V_{PP}↑ or GND↓	300		ns	
t_{HC}	Hold time clock high after V_{PP}↑ or GND↓	500		ns	
t_{HE}	Hold time enable high after V_{PP}↑ or GND↓	300		ns	
t_{HP}	Hold time polarity high or low after V_{PP}↑ or GND↓	300		ns	
t_{DHL}	Delay time high to low level output from clock		150	ns	C_L = 10pF
t_{DLH}	Delay time low to high level output from clock		200	ns	C_L = 10pF
t_{THL}	Transition time high to low level serial output		200	ns	C_L = 15pF
t_{TLH}	Transition time low to high level serial output		100	ns	C_L = 15pF
t_{ONH}	High level turn-on time Q outputs from enable		500	ns	I_O = -50 mA, V_{OH} =195V R_L = 2 kΩ to 95V
t_{ONL}	Low level turn-on time Q outputs from enable		500	ns	I_O = 50 mA, V_{OH} =130V R_L = 2 kΩ to 30V
t_{OFFH}	High level turn-off time Q outputs from enable		1000	ns	I_O = -50 mA, V_{OH} =195V R_L = 2 kΩ to 95V
t_{OFFL}	Low level turn-off time Q outputs from enable		500	ns	I_O = 50 mA, V_{OH} =130V R_L = 2 kΩ to 30V
dv/dt	Slew rate, V_{PP} or GND		45	V/µs	With one active output driving a 4.7 nF load to V_{PP} or GND

Recommended Operating Conditions

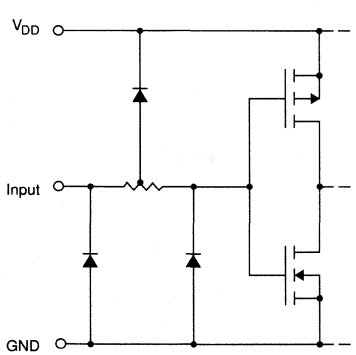
Symbol	Parameter		Min	Max	Units
V_{DD}	Logic supply voltage		4.5	5.5	V
V_{PP}	High voltage supply			230	V
V_{IH}	High-level input voltage	V_{DD} = 4.5V	3.5		V
V_{IL}	Low-level input voltage	V_{DD} = 4.5V		1	V
f_{CLK}	Clock frequency			4	MHz
T_A	Operating free-air temperature	Commercial	0	+70	°C
		Military Hi-Rel (RB)	-55	+125	°C

Note:
Power-up sequence should be the following:

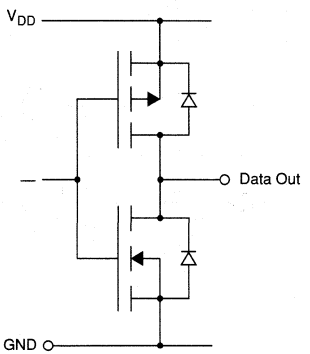
1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

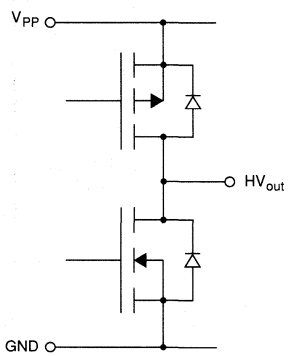
Input and Output Equivalent Circuits



Logic Inputs

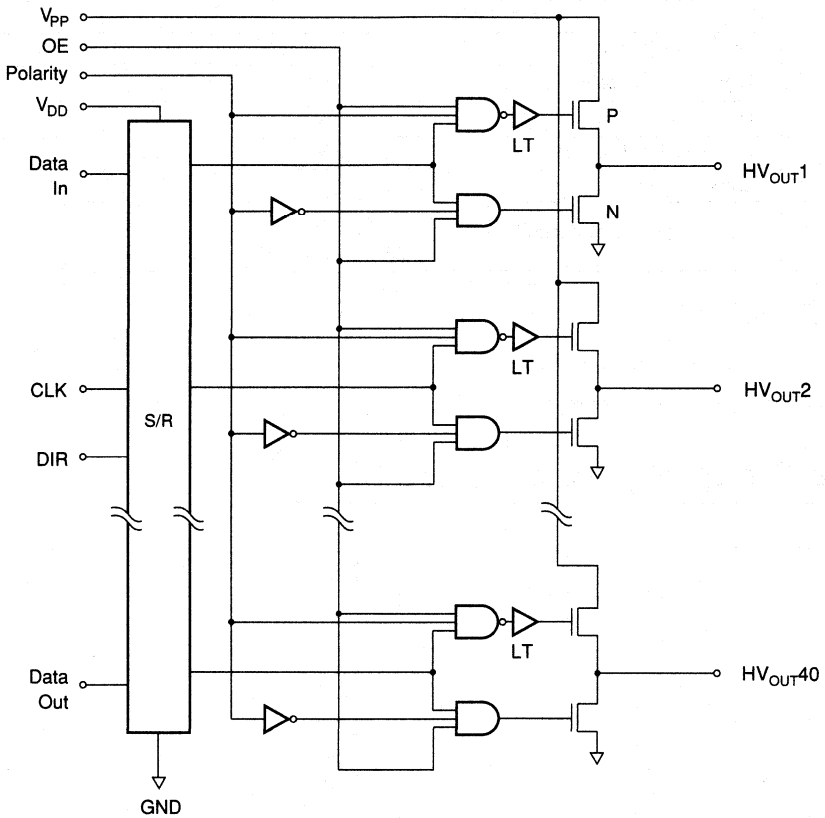


Logic Data Output



High Voltage Outputs

Functional Block Diagram



LT = Level Translator

Function Table

I/O Relations	Inputs					Outputs		
	CLK	DIR	Data	POL	OE	Shift Reg	HV Outputs	Data Out
O/P HIGH	X	X	H	H	H	*	H	
O/P OFF	X	X	L	H	H	*	HIGH-Z	*
O/P LOW	X	X	H	L	H	*	L	*
O/P OFF	X	X	L	L	H	*	HIGH-Z	*
O/P OFF	X	X	X	X	L	*	All O/P HIGH-Z	*
Load S/R, set DIR	↓	L	X	X	X	$Q_n \rightarrow Q_{n+1}$	*	Q_{40}
	↓	H	X	X	X	$Q_n \rightarrow Q_{n-1}$	*	Q_1
I/O Relation	X	L	D_{IOB}	X	X	*	*	D_{IOA}
	X	H	D_{IOA}	X	X	*	*	D_{IOB}

Notes:
H = logic high level, L = logic low level, X = irrelevant, ↓ = high-to-low transition,
$Q_1 = HV_{out}$ 1, $Q_n = HV_{out}$ (n), etc.
* = dependent on previous state and whether an O/P or S/R command occured.

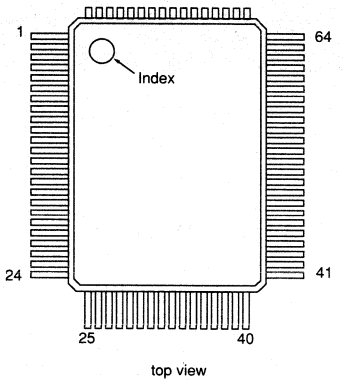
Pin Configurations

HV72
64-pin 3-sided Gullwing

Pin	Function	Pin	Function
1	$HV_{OUT}1/40$	33	NC
2	$HV_{OUT}2/39$	34	D_{IOB}
3	$HV_{OUT}3/38$	35	OE
4	$HV_{OUT}4/37$	36	NC
5	$HV_{OUT}5/36$	37	POL
6	$HV_{OUT}6/35$	38	NC
7	$HV_{OUT}7/34$	39	V_{DD}
8	$HV_{OUT}8/33$	40	NC
9	$HV_{OUT}9/32$	41	GND(Logic)
10	$HV_{OUT}10/31$	42	GND(Power)
11	$HV_{OUT}11/30$	43	NC
12	$HV_{OUT}12/29$	44	V_{PP}
13	$HV_{OUT}13/28$	45	$HV_{OUT}21/20$
14	$HV_{OUT}14/27$	46	$HV_{OUT}22/19$
15	$HV_{OUT}15/26$	47	$HV_{OUT}23/18$
16	$HV_{OUT}16/25$	48	$HV_{OUT}24/17$
17	$HV_{OUT}17/24$	49	$HV_{OUT}25/16$
18	$HV_{OUT}18/23$	50	$HV_{OUT}26/15$
19	$HV_{OUT}19/22$	51	$HV_{OUT}27/14$
20	$HV_{OUT}20/21$	52	$HV_{OUT}28/13$
21	V_{PP}	53	$HV_{OUT}29/12$
22	NC	54	$HV_{OUT}30/11$
23	GND(Power)	55	$HV_{OUT}31/10$
24	GND(Logic)	56	$HV_{OUT}32/9$
25	DIR	57	$HV_{OUT}33/8$
26	V_{DD}	58	$HV_{OUT}34/7$
27	CK	59	$HV_{OUT}35/6$
28	NC	60	$HV_{OUT}36/5$
29	NC	61	$HV_{OUT}37/4$
30	NC	62	$HV_{OUT}38/3$
31	D_{IOA}	63	$HV_{OUT}39/2$
32	NC	64	$HV_{OUT}40/1$

Note:
Pin designation for DIR H/L
Example: For DIR = H, pin 1 is HV_{OUT} 1
For DIR = L, pin 1 is HV_{OUT} 40

Package Outline



3-sided Plastic QFP 64-pin Gullwing Package

40 MHz, 64-Channel Serial To Parallel Converter With Push-Pull Outputs

Ordering Information

Device	Package Options			
	80 Lead Quad Ceramic Gullwing	80 Lead Quad Plastic Gullwing	Die	80 Lead Quad Ceramic Gullwing (MIL-STD-883 Processed*)
HV77	HV7708DG	HV7708PG	HV7708X	RBHV7708DG

* For Hi-Rel process flows, refer to page 5-3 of the Databook.

Features

- ☐ Processed with HVCMOS® technology
- ☐ 5V CMOS logic
- ☐ Output voltages up to 80V
- ☐ Low power level shifting
- ☐ Source/sink current minimum 20mA
- ☐ 40MHz equivalent data rate
- ☐ Latched data outputs
- ☐ Forward and reverse shifting options (DIR pin)
- ☐ Diode to V_{PP} allows efficient power recovery
- ☐ Outputs may be hot switched
- ☐ Hi-Rel processing available

Absolute Maximum Ratings

Supply voltage, V_{DD}[1]		-0.5V to +7.5V
Output voltage, V_{PP}		-0.5V to +90V
Logic input levels		-0.3V to V_{DD} +0.3V
Ground currrent[2]		1.5A
Continuous total power dissipation[3]	Ceramic Plastic	1500mW 1200mW
Operating temperature range		0 to 85°C
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. All voltages are referenced to GND.
2. Limited by the total power dissipated in the package.
3. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

General Description

The HV77 is a low-voltage serial to high-voltage parallel converter with push-pull outputs. This device has been designed for use as a driver for electroluminescent displays. It can also be used in any application requiring multiple output high-voltage current sourcing and sinking capability such as driving plasma panels, vacuum fluorescent displays, or large matrix LCD displays.

The device has 4 parallel 16-bit shift registers, permitting data rates 4X the speed of one (they are clocked together). There are also 64 latches and control logic to perform the polarity select and blanking of the outputs. HVout1 is connected to the first stage of the first shift register through the polarity and blanking logic. Data is shifted through the shift registers on the logic low to high transition of the clock. The DIR pin causes CCW shifting when connected to GND, and CW shifting when connected to V_{DD}. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register (HVout 64). Operation of the shift register is not affected by the $\overline{LE}$ (latch enable), $\overline{BL}$ (blanking), or the $\overline{POL}$ (polarity) inputs. Transfer of data from the shift registers to the latches occurs when the $\overline{LE}$ (latch enable) input is high. The data in the latches is stored when $\overline{LE}$ is low.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Max	Units	Conditions
I_{DD}	V_{DD} supply current			15	mA	$V_{DD} = V_{DD}$ max f_{CLK} = 10MHz
I_{PP}	High voltage supply current			100	µA	Outputs high
				100	µA	Outputs low
I_{DDQ}	Quiescent V_{DD} supply current			100	µA	All $V_{IN} = V_{DD}$
V_{OH}	High-level output	HV_{OUT}	72		V	I_O= -15mA, V_{PP} = 80V
		Data out	V_{DD} - 0.5		V	I_O= -100µA
V_{OL}	Low-level output	HV_{OUT}		8	V	I_O= 15mA, V_{PP} = 80V
		Data out		0.5	V	I_O= 100µA
I_{IH}	High-level logic input current			1	µA	$V_{IH} = V_{DD}$
I_{IL}	Low-level logic input current			-1	µA	V_{IL} = 0V

AC Characteristics (T_A = 85°C max. Logic signal inputs and Data inputs have t_r, $t_f \leq$ 5ns [10% and 90% points])

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock frequency		12	MHz	Per Register
t_{WL},t_{WH}	Clock width high or low	25		ns	
t_{SU}	Data set-up time before clock rises	10		ns	
t_H	Data hold time after clock rises	15		ns	
t_{ON}, t_{OFF}	Time from latch enable to HV_{OUT}		500	ns	C_L = 15pF
t_{DHL}	Delay time clock to data high to low		40	ns	C_L = 15pF
t_{DLH}	Delay time clock to data low to high		40	ns	C_L = 15pF
t_{DLE}*	Delay time clock to $\overline{LE}$ low to high	25		ns	
t_{WLE}	Width of $\overline{LE}$ pulse	25		ns	
t_{SLE}	$\overline{LE}$ set-up time before clock rises	0		ns	

* t_{DLE} is not required but is recommended to produce stable HV outputs and thus minimize power dissipation and current spikes (allows internal SR output to stabilize).

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Recommended Operating Conditions

Symbol	Parameter		Min	Max	Units
V_{DD}	Logic supply voltage		4.5	5.5	V
V_{PP}	Output voltage		8	80	V
V_{IH}	High-level input voltage		V_{DD} -0.5V		V
V_{IL}	Low-level input voltage		0	0.5	V
f_{CLK}	Clock frequency per register			12	MHz
T_A	Operating free-air temperature	Commercial	0	+70	°C
		Military Hi-Rel (RB)	-55	+125	

Note:

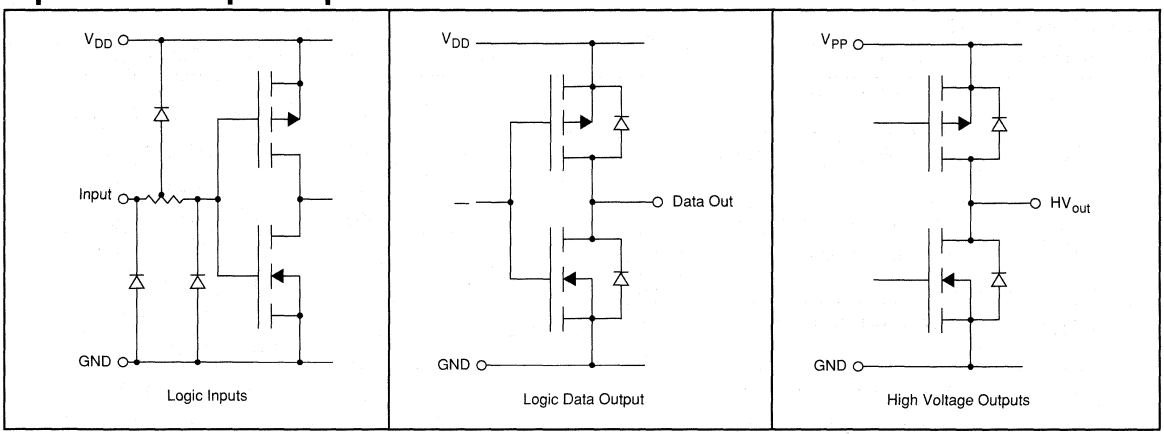
Power-up sequence should be the following:

1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

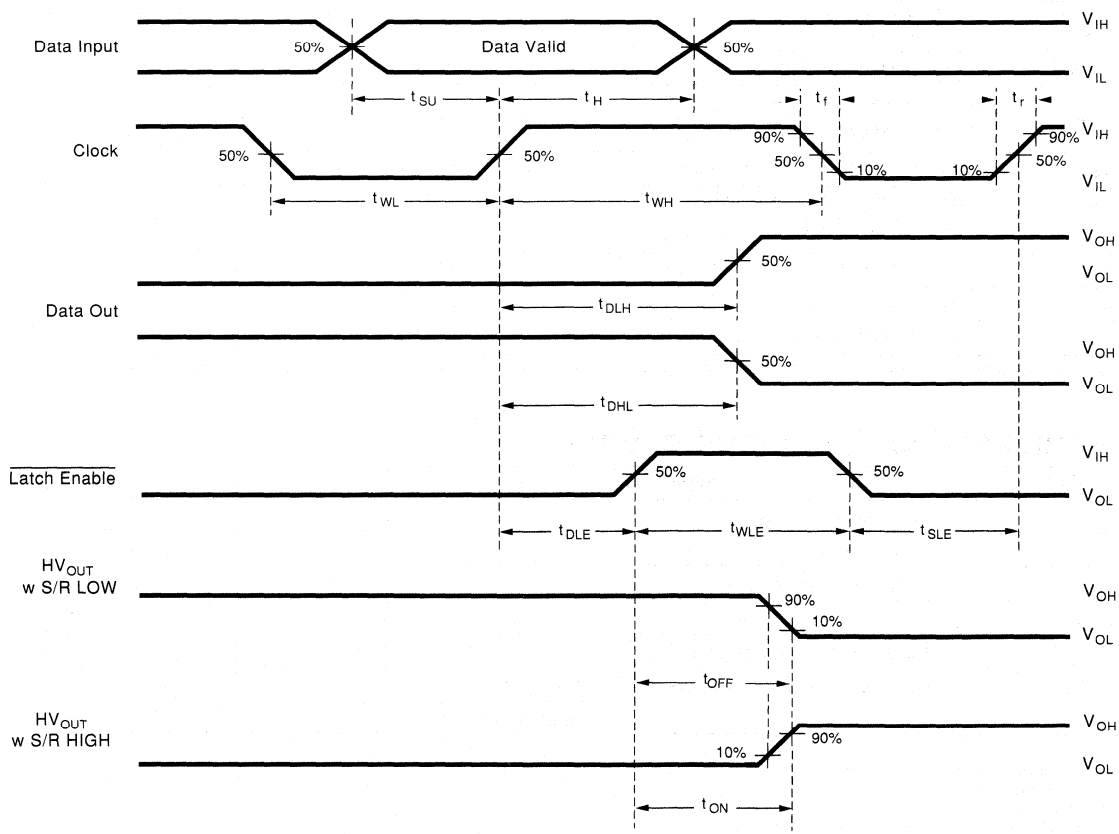
Power-down sequence should be the reverse of the above.

6. The V_{PP} should not drop below V_{DD} during operations.

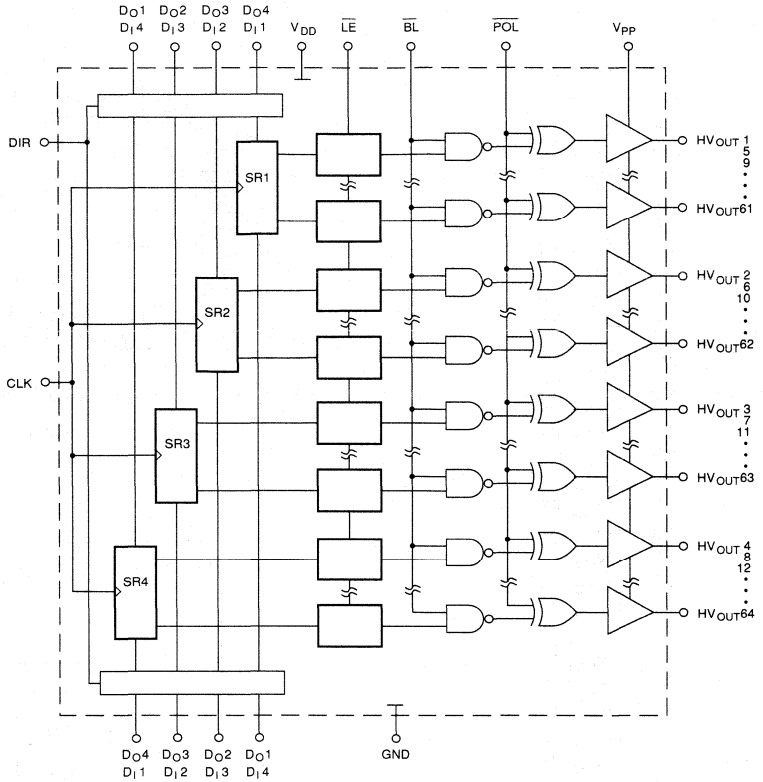
Input and Output Equivalent Circuits



Switching Waveforms



Functional Block Diagram



Note: Each SR (shift register) provides 16 outputs. SR1 supplies every fourth output starting with 1; SR2 supplies every fourth output with 2, etc.

Function Table

Function	Inputs						Outputs		
	Data	CLK	$\overline{LE}$	$\overline{BL}$	$\overline{POL}$	DIR	Shift Reg	HV Outputs	Data Out
All O/P High	X	X	X	L	L	X		H	
All O/P Low	X	X	X	L	H	X		L	
O/P Normal	X	X	X	H	H	X		No inversion	
O/P Inverted	X	X	X	H	L	X		Inversion	
Data Falls Through (Latches Transparent)	L	↑	H	H	H	X	L	L	
	H	↑	H	H	H	X	H	H	
	L	↑	H	H	L	X	L	H	
	H	↑	H	H	L	X	H	L	
Data Stored	X	X	L	H	H	X	*	Stored Data	
Latches Loaded	X	X	L	H	L	X	*	Inversion of Stored Data	
I/O Relation	$D_{I/O}1$-4A	↑	H	H	H	H	$Q_n \rightarrow Q_{n+1}$	New H or L	$D_{I/O}1 - 4B$
	$D_{I/O}1$-4A	↑	L	H	H	H	$Q_n \rightarrow Q_{n+1}$	Previous H or L	$D_{I/O}1 - 4B$
	$D_{I/O}1$-4B	↑	L	H	H	L	$Q_n \rightarrow Q_{n-1}$	Previous H or L	$D_{I/O}1 - 4A$
	$D_{I/O}1$-4B	↑	H	H	H	L	$Q_n \rightarrow Q_{n-1}$	New H or L	$D_{I/O}1 - 4A$

Notes: * = dependent on previous stage's state.
See Pin configuration for D_{IN} and D_{OUT} pin designation for CW and CCW shift

Pin Configurations

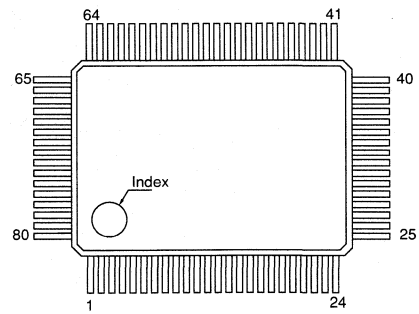
HV77

80-pin Gullwing

Pin	Function	Pin	Function
1	HV_{OUT} 24	41	HV_{OUT} 64
2	HV_{OUT} 23	42	HV_{OUT} 63
3	HV_{OUT} 22	43	HV_{OUT} 62
4	HV_{OUT} 21	44	HV_{OUT} 61
5	HV_{OUT} 20	45	HV_{OUT} 60
6	HV_{OUT} 19	46	HV_{OUT} 59
7	HV_{OUT} 18	47	HV_{OUT} 58
8	HV_{OUT} 17	48	HV_{OUT} 57
9	HV_{OUT} 16	49	HV_{OUT} 56
10	HV_{OUT} 15	50	HV_{OUT} 55
11	HV_{OUT} 14	51	HV_{OUT} 54
12	HV_{OUT} 13	52	HV_{OUT} 53
13	HV_{OUT} 12	53	HV_{OUT} 52
14	HV_{OUT} 11	54	HV_{OUT} 51
15	HV_{OUT} 10	55	HV_{OUT} 50
16	HV_{OUT} 9	56	HV_{OUT} 49
17	HV_{OUT} 8	57	HV_{OUT} 48
18	HV_{OUT} 7	58	HV_{OUT} 47
19	HV_{OUT} 6	59	HV_{OUT} 46
20	HV_{OUT} 5	60	HV_{OUT} 45
21	HV_{OUT} 4	61	HV_{OUT} 44
22	HV_{OUT} 3	62	HV_{OUT} 43
23	HV_{OUT} 2	63	HV_{OUT} 42
24	HV_{OUT} 1	64	HV_{OUT} 41
25	D_{IN} 1/D_{OUT} 4(A)	65	HV_{OUT} 40
26	D_{IN} 2/D_{OUT} 3(A)	66	HV_{OUT} 39
27	D_{IN} 3/D_{OUT} 2(A)	67	HV_{OUT} 38
28	D_{IN} 4/D_{OUT} 1(A)	68	HV_{OUT} 37
29	$\overline{LE}$	69	HV_{OUT} 36
30	CLK	70	HV_{OUT} 35
31	$\overline{BL}$	71	HV_{OUT} 34
32	V_{DD}	72	HV_{OUT} 33
33	DIR	73	HV_{OUT} 32
34	GND	74	HV_{OUT} 31
35	$\overline{POL}$	75	HV_{OUT} 30
36	D_{OUT} 4/D_{IN} 1(B)	76	HV_{OUT} 29
37	D_{OUT} 3/D_{IN} 2(B)	77	HV_{OUT} 28
38	D_{OUT} 2/D_{IN} 3(B)	78	HV_{OUT} 27
39	D_{OUT} 1/D_{IN} 4(B)	79	HV_{OUT} 26
40	V_{PP}	80	HV_{OUT} 25

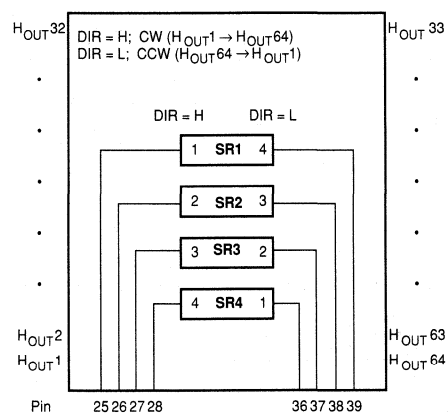
Note: Pin designation for DIR = H.
Example: For DIR = H, pin 41 is HV_{OUT} 64
For CW/CCW Shift see function table $Q_N \rightarrow Q_{N+1}$

Package Outline



top view

80-pin Gullwing Package



Supertex inc.

Product Objective Specification

20 MHz, 64-Channel Serial To Parallel Converter With Push-Pull Outputs

Ordering Information

Device	Package Options			
	80 Lead Quad Ceramic Gullwing	80 Lead Quad Plastic Gullwing	Die	80 Lead Quad Ceramic Gullwing (MIL-STD-883 Processed*)
HV78	HV7808DG	HV7808PG	HV7808X	RBHV7808DG

* For Hi-Rel process flows, refer to page 5-3 of the Databook.

Features

- ☐ Processed with HVCMOS® technology
- ☐ 5V CMOS logic
- ☐ Output voltages up to 80V
- ☐ Low power level shifting
- ☐ Source/sink current minimum 20mA
- ☐ 20MHz equivalent data rate
- ☐ Latched data outputs
- ☐ Forward and reverse shifting options (DIR pin)
- ☐ Diode to V_{PP} allows efficient power recovery
- ☐ Outputs may be hot switched
- ☐ Hi-Rel processing available

Absolute Maximum Ratings

Supply voltage, V_{DD}[1]		-0.5V to +7.5V
Output voltage, V_{PP}		-0.5V to +90V
Logic input levels		-0.3V to V_{DD} +0.3V
Ground currrent[2]		1.5A
Continuous total power dissipation[3]	Ceramic	1500mW
	Plastic	1200mW
Operating temperature range		0 to 85°C
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. All voltages are referenced to GND.
2. Limited by the total power dissipated in the package.
3. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

General Description

The HV78 is a low-voltage serial to high-voltage parallel converter with push-pull outputs. This device has been designed for use as a driver for electroluminescent displays. It can also be used in any application requiring multiple output high-voltage current sourcing and sinking capability such as driving plasma panels, vacuum fluorescent displays, or large matrix LCD displays.

The device has 2 parallel 32-bit shift registers, permitting data rates 2X the speed of one (they are clocked together). There are also 64 latches and control logic to perform the polarity select and blanking of the outputs. HVout1 is connected to the first stage of the first shift register through the polarity and blanking logic. Data is shifted through the shift registers on the logic low to high transition of the clock. The DIR pin causes CCW shifting when connected to GND, and CW shifting when connected to V_{DD}. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register (HVout 64). Operation of the shift register is not affected by the $\overline{LE}$ (latch enable), $\overline{BL}$ (blanking), or the $\overline{POL}$ (polarity) inputs. Transfer of data from the shift registers to the latches occurs when the $\overline{LE}$ (latch enable) input is high. The data in the latches is stored when $\overline{LE}$ is low.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Max	Units	Conditions
I_{DD}	V_{DD} supply current			15	mA	$V_{DD} = V_{DD}$ max f_{CLK} = 10MHz
I_{PP}	High voltage supply current			100	µA	Outputs high
				100	µA	Outputs low
I_{DDQ}	Quiescent V_{DD} supply current			100	µA	All $V_{IN} = V_{DD}$
V_{OH}	High-level output	HV_{OUT}	72		V	I_O= -15mA, V_{PP} = 80V
		Data out	V_{DD} - 0.5		V	I_O= -100µA
V_{OL}	Low-level output	HV_{OUT}		8	V	I_O= 15mA, V_{PP} = 80V
		Data out		0.5	V	I_O= 100µA
I_{IH}	High-level logic input current			1	µA	$V_{IH} = V_{DD}$
I_{IL}	Low-level logic input current			-1	µA	V_{IL} = 0V

AC Characteristics (T_A = 85°C max. Logic signal inputs and Data inputs have t_r, $t_f \leq$ 5ns [10% and 90% points])

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock frequency		12	MHz	Per Register
t_{WL},t_{WH}	Clock width high or low	25		ns	
t_{SU}	Data set-up time before clock rises	10		ns	
t_H	Data hold time after clock rises	15		ns	
t_{ON}, t_{OFF}	Time from latch enable to HV_{OUT}		500	ns	C_L = 15pF
t_{DHL}	Delay time clock to data high to low		40	ns	C_L = 15pF
t_{DLH}	Delay time clock to data low to high		40	ns	C_L = 15pF
t_{DLE}*	Delay time clock to $\overline{LE}$ low to high	25		ns	
t_{WLE}	Width of $\overline{LE}$ pulse	25		ns	
t_{SLE}	$\overline{LE}$ set-up time before clock rises	0		ns	

* t_{DLE} is not required but is recommended to produce stable HV outputs and thus minimize power dissipation and current spikes (allows internal SR output to stabilize).

Recommended Operating Conditions

Symbol	Parameter		Min	Max	Units
V_{DD}	Logic supply voltage		4.5	5.5	V
V_{PP}	Output voltage		8	80	V
V_{IH}	High-level input voltage		V_{DD} -0.5V		V
V_{IL}	Low-level input voltage		0	0.5	V
f_{CLK}	Clock frequency per register			12	MHz
T_A	Operating free-air temperature	Commercial	0	+70	°C
		Military Hi-Rel (RB)	-55	+125	

Note:

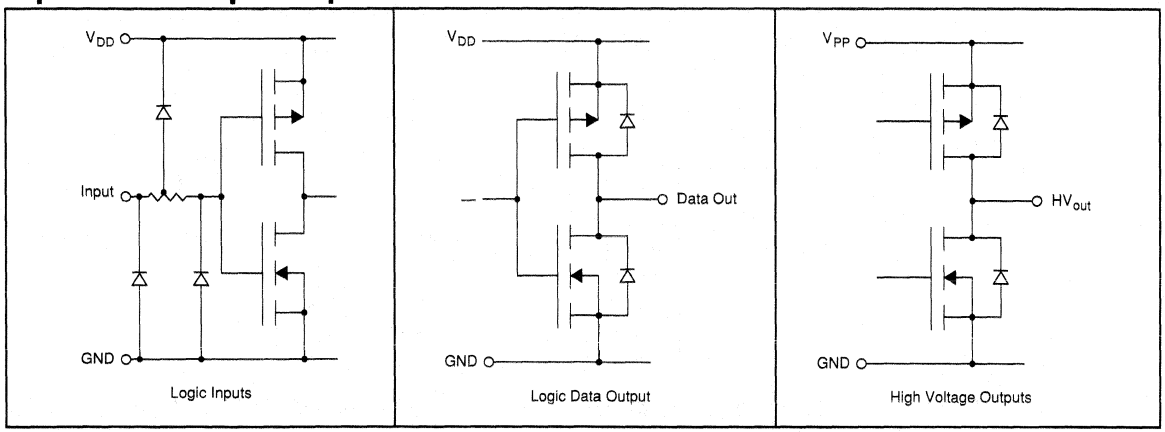
Power-up sequence should be the following:

1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

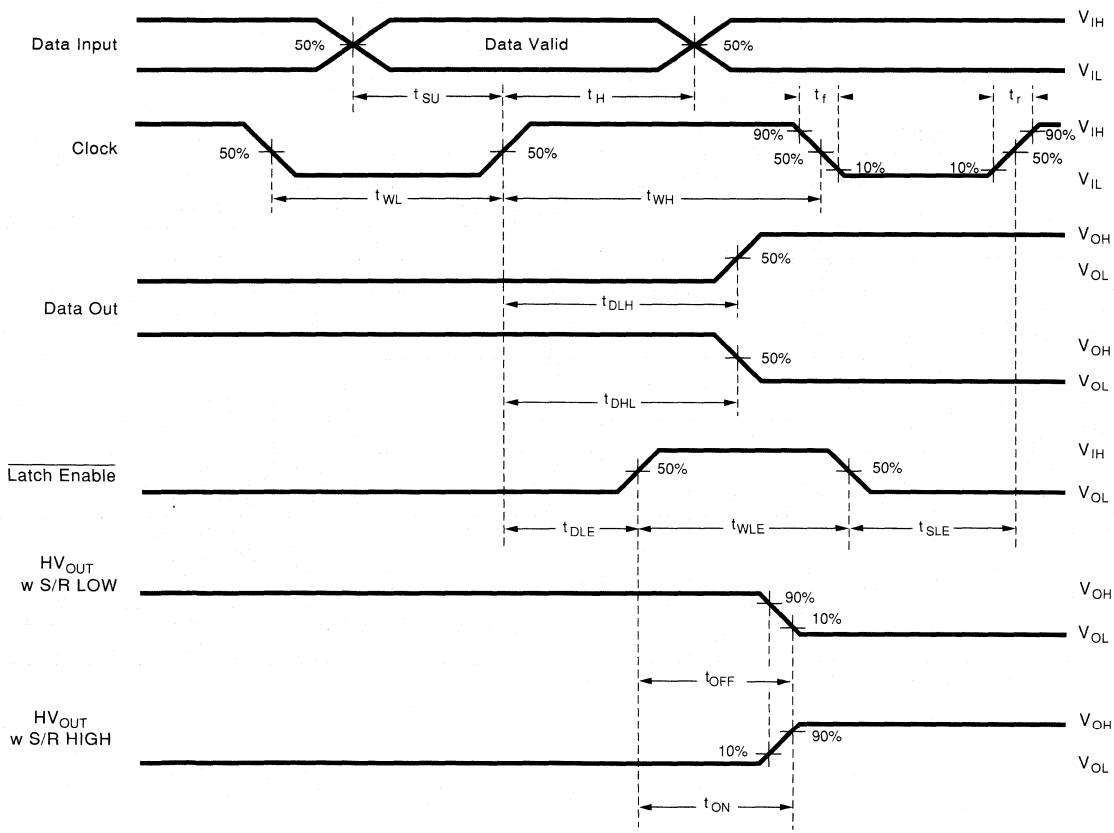
Power-down sequence should be the reverse of the above.

6. The V_{PP} should not drop below V_{DD} during operations.

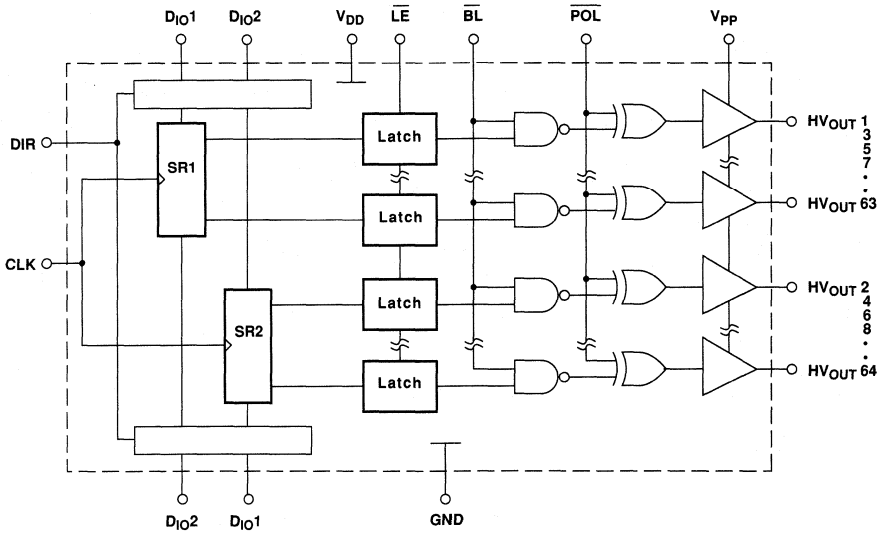
Input and Output Equivalent Circuits



Switching Waveforms



Functional Block Diagram



Function Table

Function	Inputs						Outputs		
	Data	CLK	$\overline{LE}$	$\overline{BL}$	$\overline{POL}$	DIR	Shift Reg	HV Outputs	Data Out
All O/P High	X	X	X	L	L	X		H	
All O/P Low	X	X	X	L	H	X		L	
O/P Normal	X	X	X	H	H	X		No inversion	
O/P Inverted	X	X	X	H	L	X		Inversion	
Data Falls Through (Latches Transparent)	L	↑	H	H	H	X	L	L	
	H	↑	H	H	H	X	H	H	
	L	↑	H	H	L	X	L	H	
	H	↑	H	H	L	X	H	L	
Data Stored	X	X	L	H	H	X	*	Stored Data	
Latches Loaded	X	X	L	H	L	X	*	Inversion of Stored Data	
I/O Relation	D_{OI} 1-2A	↑	H	H	H	H	$Q_n \rightarrow Q_{n+1}B$	New H or L	D_{OI}1-2B
	D_{OI} 1-2B	↑	L	H	H	L	$Q_n \rightarrow Q_{n+1}A$	Previous H or L	D_{OI}1-2A

Notes: * = dependent on previous stage's state.

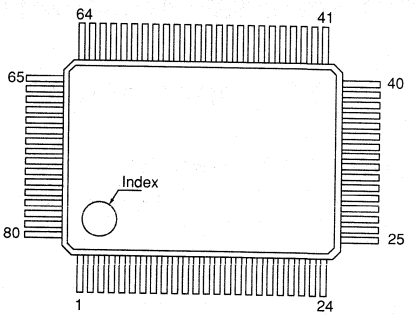
Pin Configurations

HV78
80-pin Gullwing

Pin	Function	Pin	Function
1	HV_{OUT} 24	41	HV_{OUT} 64
2	HV_{OUT} 23	42	HV_{OUT} 63
3	HV_{OUT} 22	43	HV_{OUT} 62
4	HV_{OUT} 21	44	HV_{OUT} 61
5	HV_{OUT} 20	45	HV_{OUT} 60
6	HV_{OUT} 19	46	HV_{OUT} 59
7	HV_{OUT} 18	47	HV_{OUT} 58
8	HV_{OUT} 17	48	HV_{OUT} 57
9	HV_{OUT} 16	49	HV_{OUT} 56
10	HV_{OUT} 15	50	HV_{OUT} 55
11	HV_{OUT} 14	51	HV_{OUT} 54
12	HV_{OUT} 13	52	HV_{OUT} 53
13	HV_{OUT} 12	53	HV_{OUT} 52
14	HV_{OUT} 11	54	HV_{OUT} 51
15	HV_{OUT} 10	55	HV_{OUT} 50
16	HV_{OUT} 9	56	HV_{OUT} 49
17	HV_{OUT} 8	57	HV_{OUT} 48
18	HV_{OUT} 7	58	HV_{OUT} 47
19	HV_{OUT} 6	59	HV_{OUT} 46
20	HV_{OUT} 5	60	HV_{OUT} 45
21	HV_{OUT} 4	61	HV_{OUT} 44
22	HV_{OUT} 3	62	HV_{OUT} 43
23	HV_{OUT} 2	63	HV_{OUT} 42
24	HV_{OUT} 1	64	HV_{OUT} 41
25	D_{IO} 1/D_{OI} 2(A)	65	HV_{OUT} 40
26	D_{IO} 2/D_{OI} 1(A)	66	HV_{OUT} 39
27	NC	67	HV_{OUT} 38
28	NC	68	HV_{OUT} 37
29	$\overline{LE}$	69	HV_{OUT} 36
30	CLK	70	HV_{OUT} 35
31	$\overline{BL}$	71	HV_{OUT} 34
32	V_{DD}	72	HV_{OUT} 33
33	DIR	73	HV_{OUT} 32
34	GND	74	HV_{OUT} 31
35	$\overline{POL}$	75	HV_{OUT} 30
36	D_{OI} 2/D_{IO} 1(B)	76	HV_{OUT} 29
37	D_{OI} 1/D_{IO} 2(B)	77	HV_{OUT} 28
38	NC	78	HV_{OUT} 27
39	NC	79	HV_{OUT} 26
40	V_{PP}	80	HV_{OUT} 25

Note:
Pin designation for DIR = H
Example: For DIR = H, pin 41 is HV_{OUT} 64
For CW/CCW Shift see function table for $Q_N \rightarrow Q_{N+1}$

Package Outline



top view

80-pin Gullwing Package

Product Objective Specifications

220V 40-Channel Vacuum-Fluorescent Display Driver

Ordering Information

Device	Package Options	
	60 Pin Plastic Gullwing	Die
HV701	HV701PG	HV701X
HV711	HV711PG	HV711X

Features

- ☐ 220V push-pull outputs
- ☐ 40 output lines
- ☐ 5V CMOS logic
- ☐ +2.5 / -10mA output sink/source
- ☐ Two 20-bit parallel shift registers
- ☐ 40-bit latch
- ☐ 60-pin 2-sided Gullwing
- ☐ 8MHz shift clock
- ☐ Processed with HVCMOS® technology

General Description

The HV701/711 are designed to drive vacuum fluorescent displays used in graphic applications. The 40 outputs are supplied by 40 output latches which are fed from two 20-bit shift registers that have been loaded in parallel from 2 data inputs. Data is shifted in on the HIGH-to-LOW clock transition. Logic control is provided by a latch enable (LE) and output clear ($\overline{CL}$). When $\overline{CL}$ is HIGH, data is blocked from the output: when $\overline{CL}$ is LOW all outputs are LOW.

Pin assignments for the HV711 have pin reversed from the HV701 for ease in PC board layout.

Absolute Maximum Ratings

Supply voltage,[1] V_{DD}	-0.5V to +7V
Supply voltage,[1] V_{PP}	-0.5V to +250V
Logic input levels	-0.5V to V_{DD} +0.5V
Continuous total power dissipation [2,3]	800mW
Operating temperature range	-40°C to +85°C
Storage temperature range	-65°C to +150°C
Lead temperature 1.6mm(1/16 inch) from case for 10 seconds	260°C

Notes:
1. All voltages referenced to GND
2. Duty cycle is limited by the total power dissipated in the package
3. For operation above 25°C ambient, derate linearly to 614mW/°C @ 6.4mW/°C

Electrical Characteristics (V_{DD} = 5V, V_{PP} = 220V, T_A = -40°C to 85°C unless otherwise noted)

Parameter	Symbol	Test Conditions		Min	Typ	Max	Unit
Logic supply current	I_{DD}	V_{DD} =5.5V	All outputs low			16.0	mA
		No load f_{CLK} = 6 MHz	All outputs low T_A = 25°C			12.0	mA
I_{DD} (quiesent)	I_{DDQ}	V_{DD} = 5.5V	All outputs high T_A = 25°C			100	µA
High voltage supply current	I_{PP}	V_{PP}=200V	All outputs low			250	µA
		No load	All outputs low T_A = 25°C			250	µA
			All outputs high T_A = 25°C			250	µA
High-level input voltage	V_{IH}		V_{DD} = 4.5V	3.6			V
			V_{DD} = 5.5V	4.4			V
Low-level input voltage	V_{IL}		V_{DD} = 4.5V			0.9	V
			V_{DD} = 5.5V			1.1	V
Input leak current	I_I	T_A =25°C				±1	µA
Input capacitance	C_I	T_A =25°C				25	pF
High-level data output voltage	V_{OH}	I_O = -0.1mA	V_{DD} = 4.5V	3.6			V
			V_{DD} = 5.5V	4.4			V
Low-level data output voltage	V_{OL}	I_O = +0.1mA	V_{DD} = 4.5V			0.9	V
			V_{DD} = 5.5V			1.1	V
High-level output voltage	V_{HVOH}	I_{HVO} = -1.0mA, T_A =25°C		218			V
Low-level output voltage	V_{HVOL}	I_{HVO} = +0.5mA, T_A =25°C				2.0	V
High-level output current	I_{HVOH}	V_{HVO} = 195V T_A =25°C		-10			mA
Low-level output current	I_{HVOL}	V_{HVO} = 10V, T_A =25°C		2.5			mA

Switching Characteristics (V_{DD} = 5V, V_{PP} = 220V, T_A = 25°C unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Delay time, clk to data out	t_{PD}	See Figure 1,2			150	ns
Delay time high voltage output, low to high	t_{DLH}	See Figure 1, 2,[1] Each HVO [2]			4.0	µs
Delay time high voltage output, high to low	t_{DHL}	See Figure 1, 2,[1] Each HVO [2]			0.3	µs
Transition time high voltage output, low to high	t_{TLH}	See Figure 1, 2,[1] Each HVO [2]			6.0	µs
Transition time high voltage output, high to low	t_{THL}	See Figure 1, 2,[1] Each HVO [2]			0.3	µs

Notes:
1. The values of t_{DLH} and t_{DHL} are the delay times from $\overline{CL}$.
2. High voltage output terminal.

Recommended Operating Conditions

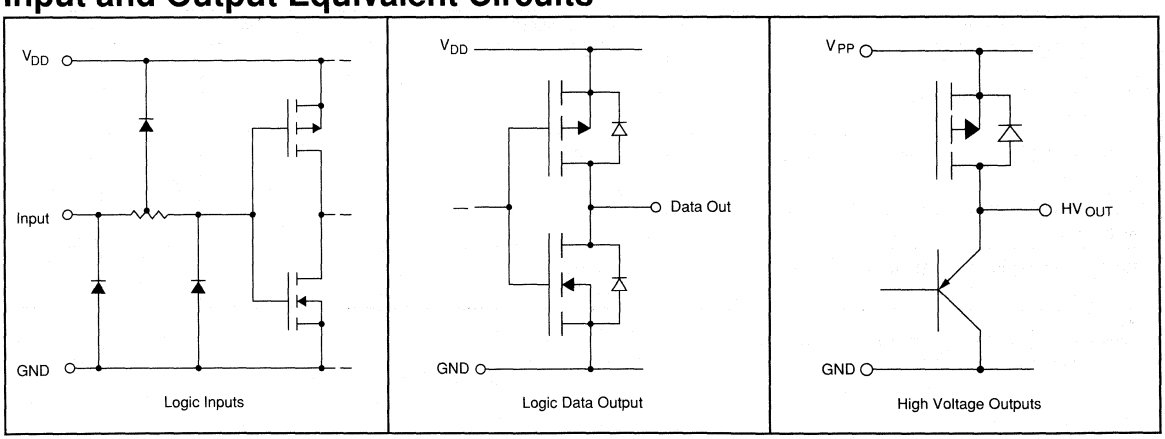
Parameter		Symbol	Conditions		Min	Max	Unit
Supply voltage		V_{DD}	Logic Supply		4.5	5.5	V
Supply voltage		V_{PP}	High voltage supply		25	220	V
High-level input voltage		V_{IH}	Each input	V_{DD} = 4.5V	3.6		V
				V_{DD} = 5.5V	4.4		V
Low-level input voltage		V_{IL}	Each input	V_{DD} = 4.5		0.9	V
				V_{DD} = 5.5		1.1	V
High-level output current		I_{HVOH}	Each HVO*			-10	mA
Low-level output current		I_{HVOL}	Each HVO*			2.5	mA
Clock frequency		f_{CLK}	Cascade			6.0	MHz
Clock pulse width		$t_{w(CLK)}$	See Figure 1, 2		70		ns
Data setup time		t_{su}	See Figure 1, 2		20		ns
Data hold time		t_h	See Figure 1, 2		45		ns
Data pulse width		$t_{w(D)}$	See Figure 1, 2		145		ns
Latch enable pulse width		$t_{w(LE)}$	See Figure 1, 2		80		ns
Data setup time	CLK-LE	$t_{su(CLK-LE)}$	See Figure 1, 2		45		ns
Data setup time	LE-CLK	$t_{su(LE-CLK)}$	See Figure 1, 2		10		ns
Data setup time	LE-$\overline{CL}$	$t_{su(LE-\overline{CL})}$	See Figure 1, 2		10		µs
Clear pulse width		$t_{w(\overline{CL})}$	See Figure 1, 2		2		µs
Operating free-air temperature range		T_{ope}			-40	+85	°C

Note:
HVO*; High voltage output terminal
Power-up sequence should be the following:

1. Connect ground.
2. Apply VDD.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply VPP.

Power-down sequence should be the reverse of the above.

Input and Output Equivalent Circuits



Parameter Measurement Information

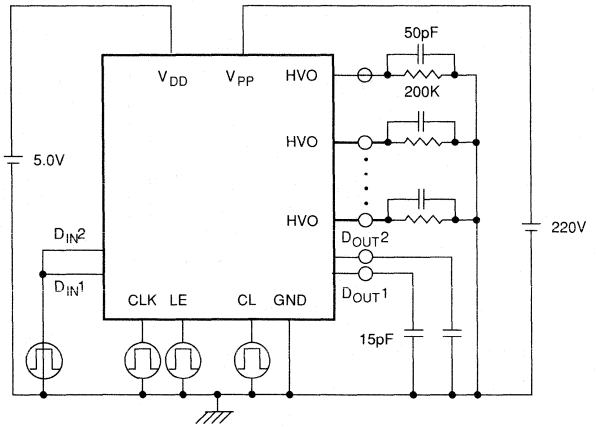


Figure 1. Test Circuit

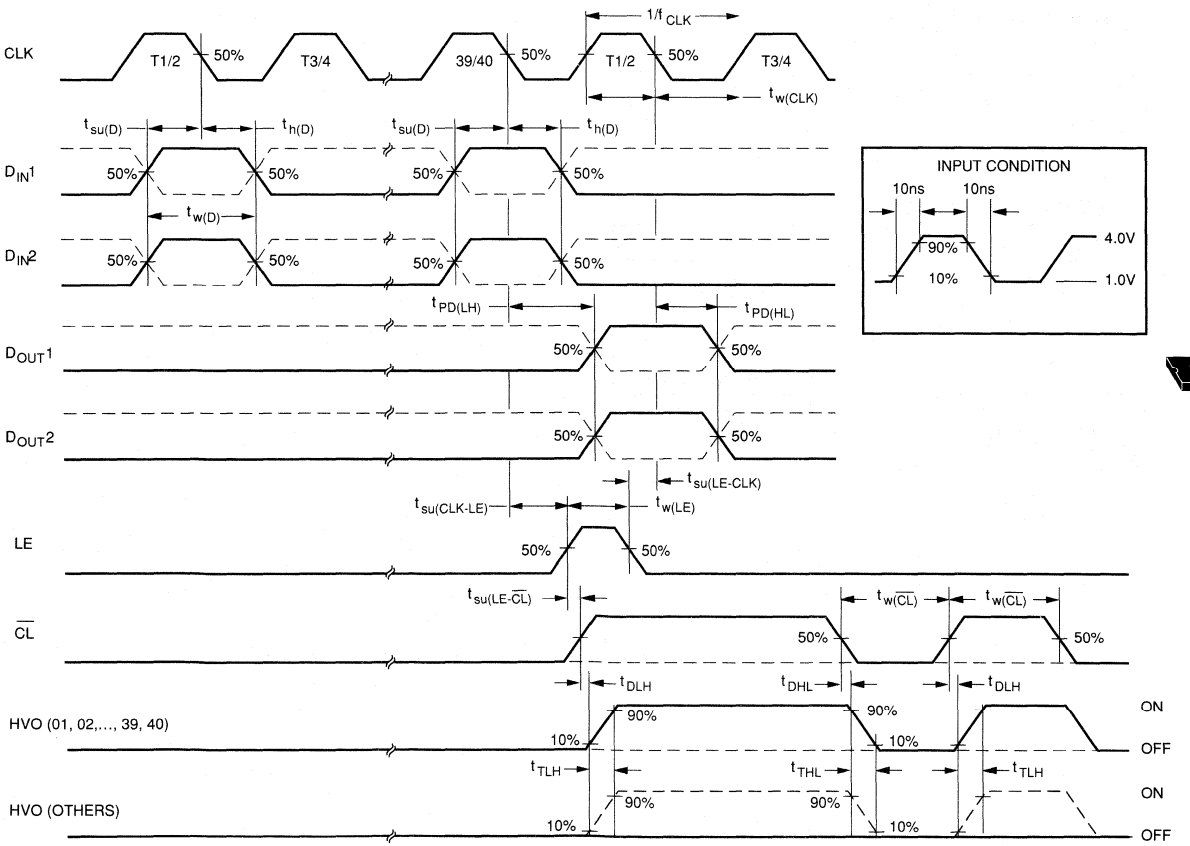
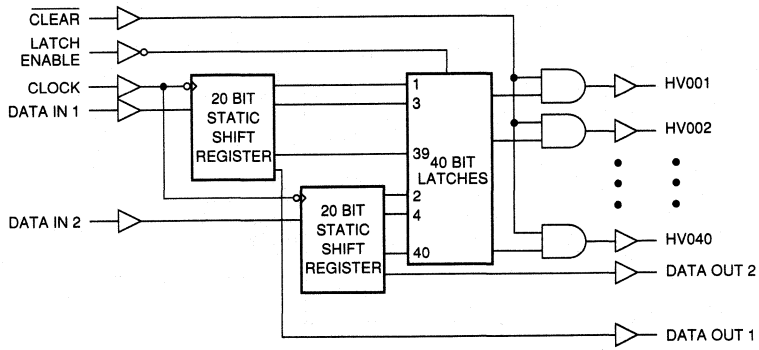


Figure 2. Timing Chart

Logic Diagram



Input Truth Table

CLK	Shift Register
↓	Data is Loaded
No Change	*

Output Truth Table

Data	LE	$\overline{CLR}$	Output
X	X	L	All O/P Low
H	H	H	High
L	H	H	Low
X	L	H	Previous Latch Data

Note:
High = high level, L = low level, X = high or low level,
↓ = high-to-low level transition
* Previous state

Pin Configurations

HV701
60 Pin FlatPackage

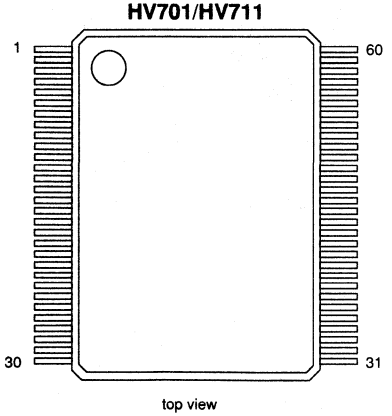
Pin	Function	Pin	Function
1	HV_{OUT} 36	31	D_{IN} 1
2	HV_{OUT} 35	32	D_{IN} 2
3	HV_{OUT} 34	33	NC
4	HV_{OUT} 33	34	CLK
5	HV_{OUT} 32	35	NC
6	HV_{OUT} 31	36	$\overline{CL}$
7	HV_{OUT} 30	37	NC
8	HV_{OUT} 29	38	NC
9	HV_{OUT} 28	39	V_{PP}
10	HV_{OUT} 27	40	NC
11	HV_{OUT} 26	41	HV_{OUT} 1
12	HV_{OUT} 25	42	HV_{OUT} 2
13	HV_{OUT} 24	43	HV_{OUT} 3
14	HV_{OUT} 23	44	HV_{OUT} 4
15	HV_{OUT} 22	45	HV_{OUT} 20
16	HV_{OUT} 21	46	HV_{OUT} 19
17	HV_{OUT} 37	47	HV_{OUT} 18
18	HVout 38	48	HV_{OUT} 17
19	HV_{OUT} 39	49	HV_{OUT} 16
20	HV_{OUT} 40	50	HV_{OUT} 15
21	NC	51	HV_{OUT} 14
22	V_{PP}	52	HV_{OUT} 13
23	NC	53	HV_{OUT} 12
24	GND	54	HV_{OUT} 11
25	NC	55	HV_{OUT} 10
26	LE	56	HV_{OUT} 9
27	NC	57	HV_{OUT} 8
28	V_{DD}	58	HV_{OUT} 7
29	D_{OUT} 2	59	HV_{OUT} 6
30	D_{OUT} 1	60	HV_{OUT} 5

HV711
60 Pin FlatPackage

Pin	Function	Pin	Function
1	HV_{OUT} 5	31	D_{OUT}1
2	HV_{OUT} 6	32	D_{OUT} 2
3	HV_{OUT} 7	33	V_{DD}
4	HV_{OUT} 8	34	NC
5	HV_{OUT} 9	35	LE
6	HV_{OUT} 10	36	NC
7	HV_{OUT} 11	37	GND
8	HV_{OUT} 12	38	NC
9	HV_{OUT} 13	39	V_{PP}
10	HV_{OUT} 14	40	NC
11	HV_{OUT} 15	41	HV_{OUT} 40
12	HV_{OUT} 16	42	HV_{OUT} 39
13	HV_{OUT} 17	43	HV_{OUT} 38
14	HV_{OUT} 18	44	HV_{OUT} 37
15	HV_{OUT} 19	45	HV_{OUT} 21
16	HV_{OUT} 20	46	HV_{OUT} 22
17	HV_{OUT} 4	47	HV_{OUT} 23
18	HV_{OUT} 3	48	HV_{OUT} 24
19	HV_{OUT} 2	49	HV_{OUT} 25
20	HV_{OUT} 1	50	HV_{OUT} 26
21	NC	51	HV_{OUT} 27
22	V_{PP}	52	HV_{OUT} 28
23	NC	53	HV_{OUT} 29
24	NC	54	HV_{OUT} 30
25	$\overline{CL}$	55	HV_{OUT} 31
26	NC	56	HV_{OUT} 32
27	CLK	57	HV_{OUT} 33
28	NC	58	HV_{OUT} 34
29	D_{IN} 2	59	HV_{OUT} 35
30	D_{IN} 1	60	HV_{OUT} 36

Package Outline

HV701/HV711



top view

Product Objective Specifications

220V 40-Channel Vacuum-Fluorescent Display Driver

Ordering Information

Device	Package Options	
	60 Pin Plastic Gullwing	Die
HV702	HV702PG	HV702X
HV712	HV712PG	HV712X

Features

- ☐ 220V push-pull outputs
- ☐ 40 output lines
- ☐ 5V CMOS logic
- ☐ +2.5 / -10mA output sink/source
- ☐ 40-bit shift register
- ☐ 40-bit latch
- ☐ 60-pin 2-sided Gullwing
- ☐ 8MHz shift clock
- ☐ Processed with HVCMOS® technology

General Description

The HV702/712 are designed to drive vacuum fluorescent displays used in graphic applications. The 40 outputs are supplied by 40 output latches which are fed from a 40-bit shift register. Data is shifted in on the HIGH-to-LOW clock transition. Logic control is provided by a latch enable (LE) and output clear ($\overline{CL}$). When $\overline{CL}$ is HIGH, data is blocked from the output: when $\overline{CL}$ is LOW all outputs are LOW.

Pin assignments for the HV712 have pin reversed from the HV702 for ease in PC board layout.

Absolute Maximum Ratings

Supply voltage,[1] V_{DD}	-0.5V to +7V
Supply voltage,[1] V_{PP}	-0.5V to +250V
Logic input levels	-0.5V to V_{DD} +0.5V
Continuous total power dissipation [2, 3]	800mW
Operating temperature range	-40°C to +85°C
Storage temperature range	-65°C to +150°C
Lead temperature 1.6mm(1/16 inch) from case for 10 seconds	260°C

Notes:
1. All voltages referenced to GND
2. Duty cycle is limited by the total power dissipated in the package
3. For operation above 25°C ambient, derate linearly to 614mW/°C @ 6.4mW/°C

Electrical Characteristics (V_{DD} = 5V, V_{PP} = 220V, T_A = -40°C to 85°C unless otherwise noted)

Parameter	Symbol	Test Conditions		Min	Typ	Max	Unit
Logic supply current	I_{DD}	V_{DD} =5.5V	All outputs low			16.0	mA
		No load f_{CLK} = 6MHz	All outputs low T_A = 25°C			12.0	mA
I_{DD} (quiesent)	I_{DDQ}	V_{DD} = 5.5V T_A = 25°C	All outputs high			100	µA
High voltage supply current	I_{PP}	V_{PP}=200V	All outputs low			250	µA
		No load T_A = 25°C	All outputs low			250	µA
		T_A = 25°C	All outputs high			250	µA
High-level input voltage	V_{IH}		V_{DD} = 4.5V	3.6			V
			V_{DD} = 5.5V	4.4			V
Low-level input voltage	V_{IL}		V_{DD} = 4.5V			0.9	V
			V_{DD} = 5.5V			1.1	V
Input leak current	I_I	T_A =25°C				±1	µA
Input capacitance	C_I	T_A =25°C				25	pF
High-level data output voltage	V_{OH}	I_O = -0.1mA	V_{DD} = 4.5V	3.6			V
			V_{DD} = 5.5V	4.4			V
Low-level data output voltage	V_{OL}	I_O = +0.1mA	V_{DD} = 4.5V			0.9	V
			V_{DD} = 5.5V			1.1	V
High-level output voltage	V_{HVOH}	I_{HVO} = -1.0mA, T_A =25°C		218			V
Low-level output voltage	V_{HVOL}	I_{HVO} = +0.5mA, T_A =25°C				2.0	V
High-level output current	I_{HVOH}	V_{HVO} = 195V T_A =25°C		-10			mA
Low-level output current	I_{HVOL}	V_{HVO} = 10V, T_A =25°C		2.5			mA

Switching Characteristics (V_{DD} = 5V, V_{PP} = 220V, T_A = 25°C unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Delay time, clk to data out	t_{PD}	See Figure 1,2			150	ns
Delay time high voltage output, low to high	t_{DLH}	See Figure 1, 2,[1] Each HVO [2]			4.0	µs
Delay time high voltage output, high to low	t_{DHL}	See Figure 1, 2,[1] Each HVO [2]			0.3	µs
Transition time high voltage output, low to high	t_{TLH}	See Figure 1, 2,[1] Each HVO [2]			6.0	µs
Transition time high voltage output, high to low	t_{THL}	See Figure 1, 2,[1] Each HVO [2]			0.3	µs

Notes:
1. The values of t_{DLH} and t_{DHL} are the delay times from $\overline{CL}$.
2. High voltage output terminal.

Recommended Operating Conditions

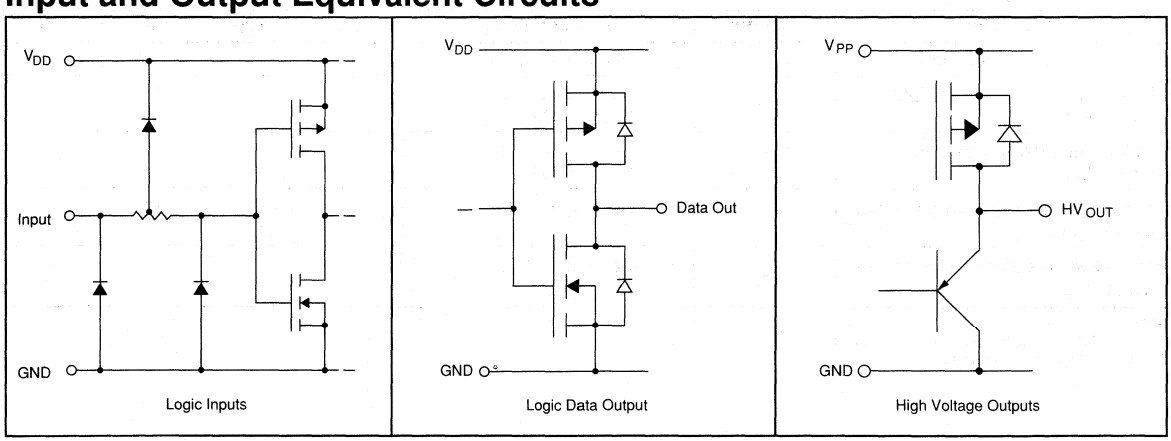
Parameter		Symbol	Conditions		Min	Max	Unit
Supply voltage		V_{DD}	Logic Supply		4.5	5.5	V
Supply voltage		V_{PP}	High voltage supply		25	220	V
High-level input voltage		V_{IH}	Each input	V_{DD} = 4.5V	3.6		V
				V_{DD} = 5.5V	4.4		V
Low-level input voltage		V_{IL}	Each input	V_{DD} = 4.5		0.9	V
				V_{DD} = 5.5		1.1	V
High-level output current		I_{HVOH}	Each HVO*			-10	mA
Low-level output current		I_{HVOL}	Each HVO*			2.5	mA
Clock frequency		f_{CLK}	Cascade			6.0	MHz
Clock pulse width		$t_{w(CLK)}$	See Figure 1, 2		70		ns
Data setup time		t_{su}	See Figure 1, 2		20		ns
Data hold time		t_h	See Figure 1, 2		45		ns
Data pulse width		$t_{w(D)}$	See Figure 1, 2		145		ns
Latch enable pulse width		$t_{w(LE)}$	See Figure 1, 2		80		ns
Data setup time	CLK-LE	$t_{su(CLK-LE)}$	See Figure 1, 2		45		ns
Data setup time	LE-CLK	$t_{su(LE-CLK)}$	See Figure 1, 2		10		ns
Data setup time	LE-$\overline{CL}$	$t_{su(LE-\overline{CL})}$	See Figure 1, 2		10		µs
Clear pulse width		$t_{w(\overline{CL})}$	See Figure 1, 2		2		µs
Operating free-air temperature range		T_{ope}			-40	+85	°C

Note:
HVO*; High voltage output terminal
Power-up sequence should be the following:

1. Connect ground.
2. Apply VDD.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply VPP.

Power-down sequence should be the reverse of the above.

Input and Output Equivalent Circuits



Parameter Measurement Information

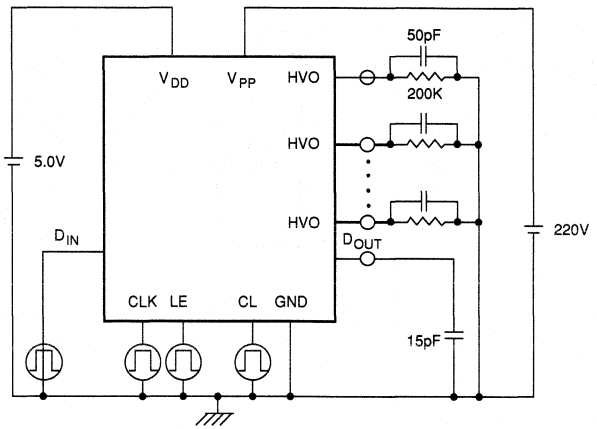


Figure 1. Test Circuit

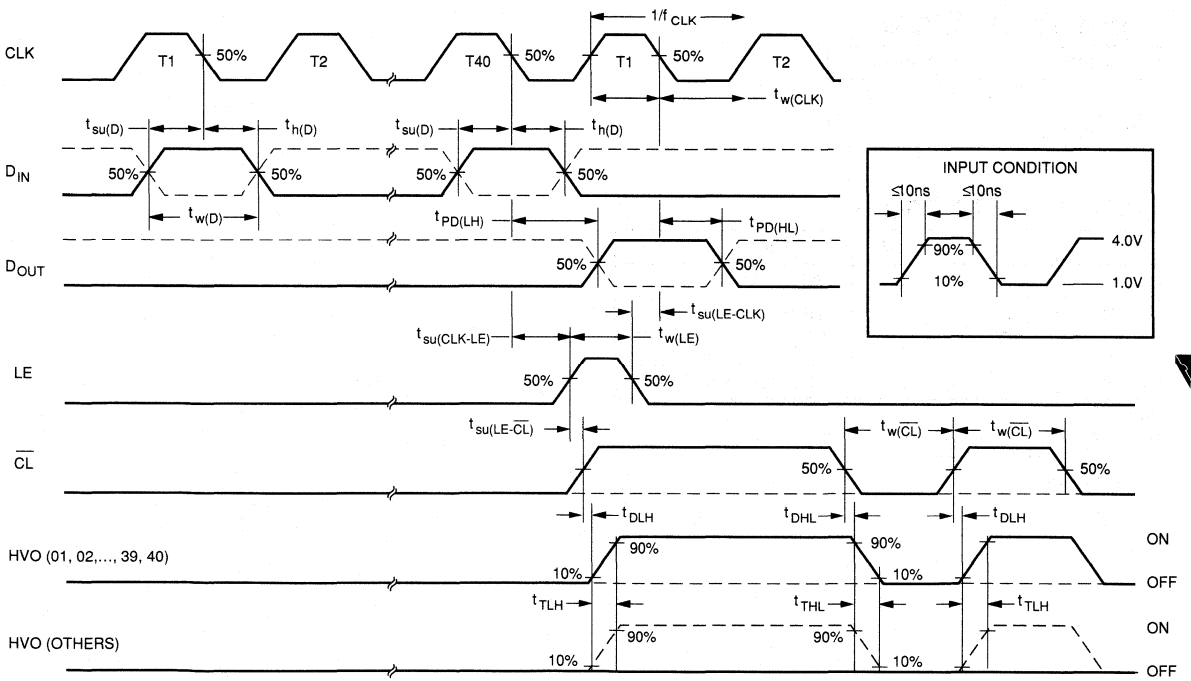
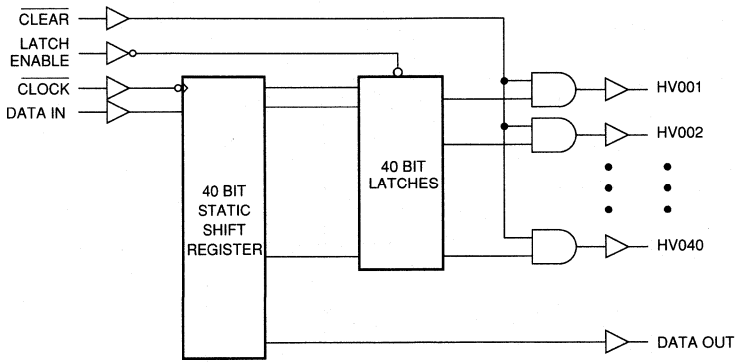


Figure 2. Timing Chart

Logic Diagram



Input Truth Table

CLK	Shift Register
↓	Data is Loaded
No Change	*

Output Truth Table

Data	LE	$\overline{CLR}$	Output
X	X	L	All O/P Low
H	H	H	High
L	H	H	Low
X	L	H	Previous Latch Data

Note:
High = high level, L = low level, X = high or low level,
↓ = high-to-low level transition
* Previous state

Pin Configurations

HV702
60 Pin FlatPackage

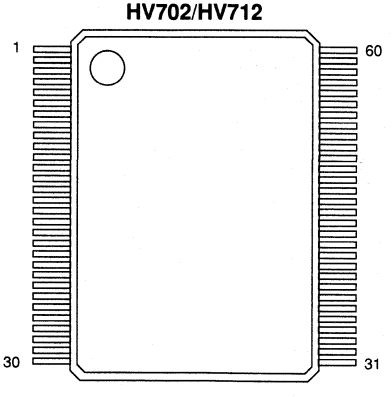
Pin	Function	Pin	Function
1	HV_{OUT} 36	31	D_{IN}
2	HV_{OUT} 35	32	NC
3	HV_{OUT} 34	33	NC
4	HV_{OUT} 33	34	CLK
5	HV_{OUT} 32	35	NC
6	HV_{OUT} 31	36	$\overline{CL}$
7	HV_{OUT} 30	37	NC
8	HV_{OUT} 29	38	NC
9	HV_{OUT} 28	39	V_{PP}
10	HV_{OUT} 27	40	NC
11	HV_{OUT} 26	41	HV_{OUT} 1
12	HV_{OUT} 25	42	HV_{OUT} 2
13	HV_{OUT} 24	43	HV_{OUT} 3
14	HV_{OUT} 23	44	HV_{OUT} 4
15	HV_{OUT} 22	45	HV_{OUT} 20
16	HV_{OUT} 21	46	HV_{OUT} 19
17	HV_{OUT} 37	47	HV_{OUT} 18
18	HV_{OUT} 38	48	HV_{OUT} 17
19	HV_{OUT} 39	49	HV_{OUT} 16
20	HV_{OUT} 40	50	HV_{OUT} 15
21	NC	51	HV_{OUT} 14
22	V_{PP}	52	HV_{OUT} 13
23	NC	53	HV_{OUT} 12
24	GND	54	HV_{OUT} 11
25	NC	55	HV_{OUT} 10
26	LE	56	HV_{OUT} 9
27	NC	57	HV_{OUT} 8
28	V_{DD}	58	HV_{OUT} 7
29	NC	59	HV_{OUT} 6
30	D_{OUT}	60	HV_{OUT} 5

HV712
60 Pin FlatPackage

Pin	Function	Pin	Function
1	HV_{OUT} 5	31	D_{OUT}
2	HV_{OUT} 6	32	NC
3	HV_{OUT} 7	33	V_{DD}
4	HV_{OUT} 8	34	NC
5	HV_{OUT} 9	35	LE
6	HV_{OUT} 10	36	NC
7	HV_{OUT} 11	37	GND
8	HV_{OUT} 12	38	NC
9	HV_{OUT} 13	39	V_{PP}
10	HV_{OUT} 14	40	NC
11	HV_{OUT} 15	41	HV_{OUT} 40
12	HV_{OUT} 16	42	HV_{OUT} 39
13	HV_{OUT} 17	43	HV_{OUT} 38
14	HV_{OUT} 18	44	HV_{OUT} 37
15	HV_{OUT} 19	45	HV_{OUT} 21
16	HV_{OUT} 20	46	HV_{OUT} 22
17	HV_{OUT} 4	47	HV_{OUT} 23
18	HV_{OUT} 3	48	HV_{OUT} 24
19	HV_{OUT} 2	49	HV_{OUT} 25
20	HV_{OUT} 1	50	HV_{OUT} 26
21	NC	51	HV_{OUT} 27
22	V_{PP}	52	HV_{OUT} 28
23	NC	53	HV_{OUT} 29
24	NC	54	HV_{OUT} 30
25	$\overline{CL}$	55	HV_{OUT} 31
26	NC	56	HV_{OUT} 32
27	CLK	57	HV_{OUT} 33
28	NC	58	HV_{OUT} 34
29	NC	59	HV_{OUT} 35
30	D_{IN}	60	HV_{OUT} 36

Package Outline

HV702/HV712



top view

32-Channel Serial To Parallel Converter With High Voltage Push-Pull Outputs

Ordering Information

Device	Recommended Operating V_{PP} max	Package Options		
		44 J-Lead Quad Ceramic Chip Carrier	44 J-Lead Quad Plastic Chip Carrier	Dice in waffle pack
HV83	80V	HV8308DJ	HV8308PJ	HV8308X
HV84	80V	HV8408DJ	HV8408PJ	HV8408X

Features

- ☐ Processed with HVCMOS® technology
- ☐ 5V CMOS compatible inputs
- ☐ Low power level shifting
- ☐ Source/sink current minimum 20mA
- ☐ Shift register speed 8MHz
- ☐ Latched data outputs
- ☐ Forward and reverse shifting options
- ☐ Diode to V_{PP} allows efficient power recovery

Absolute Maximum Ratings[1]

Supply voltage, V_{DD}[2]		-0.5V to +7V
Supply voltage, V_{PP}		-0.5V to +80V
Logic input levels[2]		-0.5 to V_{DD} + 0.5V
Ground currrent[3]		1.5A
Continuous total power dissipation[4]	Plastic	1200mW
	Ceramic	1500mW
Operating temperature range	Plastic	0°C to +70°C
	Ceramic	-40°C to +85°C
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. Device will survive (but operation may not be specified or guaranteed) at these extremes.
2. All voltages are referenced to GND.
3. Duty cycle is limited by the total power dissipated in the package.
4. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

General Description

The HV83 and HV84 are low voltage serial to high voltage parallel converters wtih push-pull outputs. These devices have been designed for use as drivers for AC-electroluminescent displays. They can also be used in any application requiring multiple output high voltage current sourcing and sinking capabilities such as driving plasma panels, vacuum fluorescent, or large matrix LCD displays.

These devices consist of a 32-bit shift register, 32 latches, and control logic to enable outputs. Q1 is connected to the first stage of the shift register through the Output Enable logic. Data is shifted through the shift register on the low to high transition of the clock. The HV84 shifts in the counterclockwise direction when viewed from the top of the package and the HV83 shifts in the clockwise direction. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register (32). Operation of the shift register is not affected by the LE (latch enable) or the OE (output enable) inputs. Transfer of data from the shift register to the latch occurs when the LE input is high. The data in the latch is retained when LE is low.

Electrical Characteristics (V_{PP} = 60V, V_{DD} = 5V, T_A =25°C)

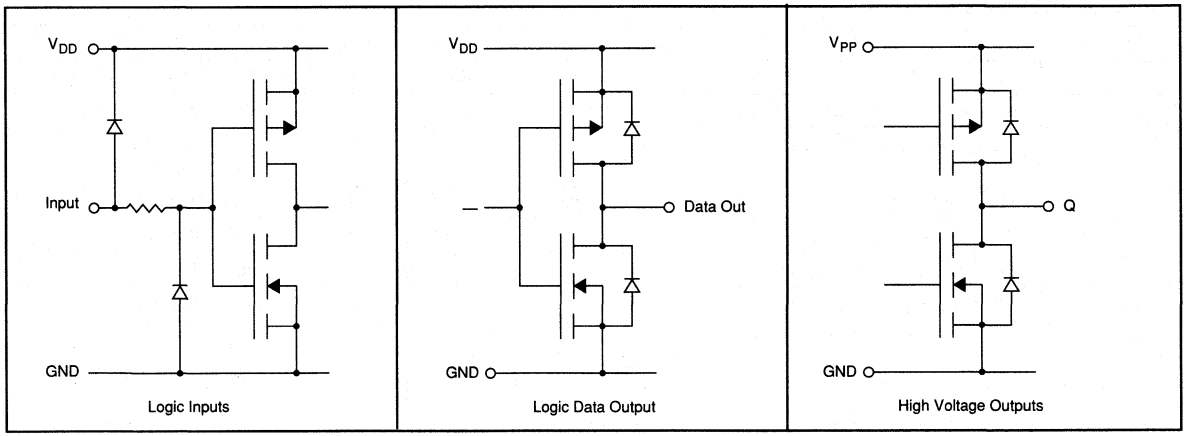
DC Characteristics

Symbol	Parameter	Min	Max	Units	Conditions
I_{PP}	V_{PP} Supply Current		100	µA	Q outputs HIGH to LOW
I_{DDQ}	I_{DD} Supply Current (Quiescent)		100	µA	All inputs = V_{DD} or GND
I_{DD}	I_{DD} Supply Current (Operating)		15	mA	V_{DD} = V_{DD} max, f_{CLK} = 8 MHz
V_{OH} (Data)	Shift Register Output Voltage	4.5		V	When driving HIGH
V_{OL} (Data)	Shift Register Output Voltage		0.5	V	When driving LOW
I_{IH}	Current Leakage, any input		1	µA	Input = HIGH
I_{IL}	Current Leakage, any input		-1	µA	Input = LOW
V_{OC}	Q Output Clamp Diode Voltage		-1.5	V	I_{OL} = -100mA
V_{OH}	Q Output when Sourcing	52		V	I_{OH} = -20mA, 0 to 70°C
V_{OL}	Q Output when Sinking		8	V	I_{OL} = 20mA, 0 to 70°C

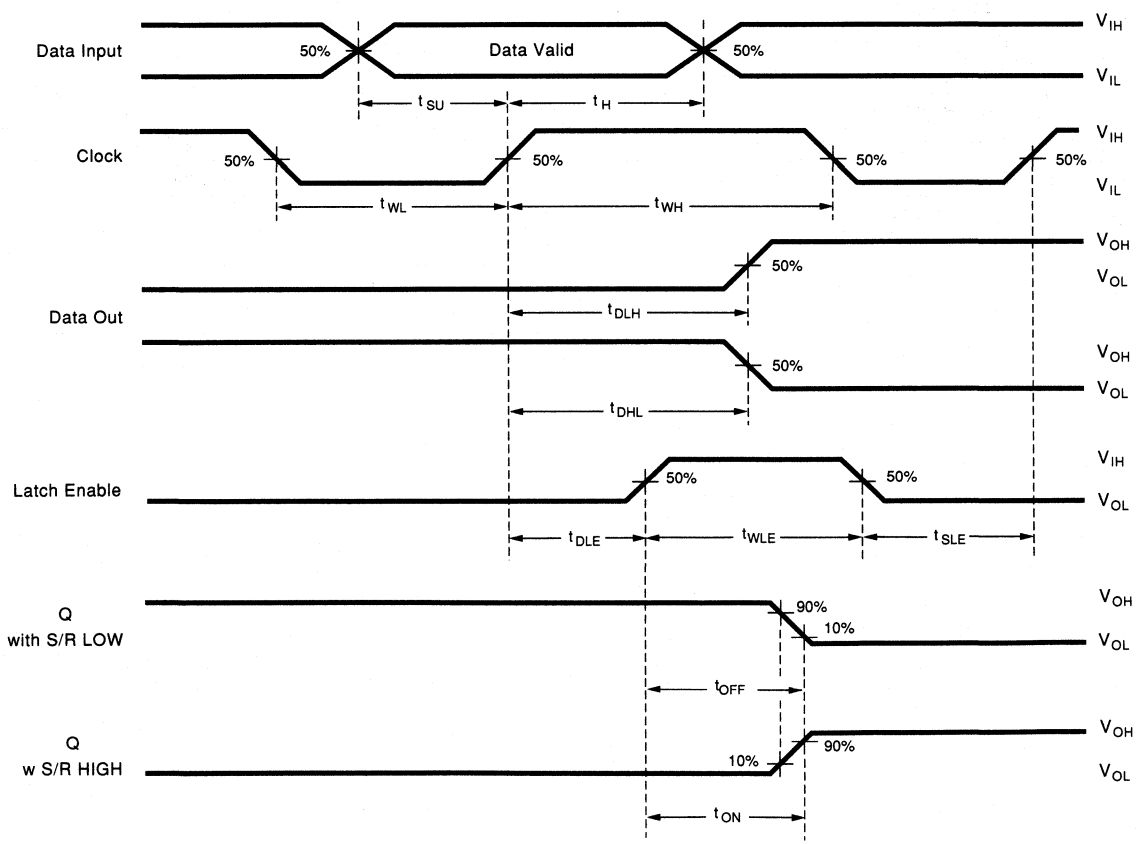
AC Characteristics

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock Frequency		8	MHz	
t_{WL} or t_{WH}	Clock width, HIGH or LOW	62		ns	
t_{SU}	Setup time before CLK rises	25		ns	
t_H	Hold time after CLK rises	10		ns	
t_{DLH} (Data)	Data Output Delay after L to H CLK		100	ns	C_L = 15pF
t_{DHL} (Data)	Data Output Delay after H to L CLK		100	ns	C_L = 15pF
t_{DLE}	LE Delay after L to H CLK	50		ns	
t_{WLE}	Width of LE Pulse	50		ns	
t_{SLE}	LE Setup Time before L to H CLK	50		ns	
t_{ON}	Delay from LE to Q, L to H		500	ns	
t_{OFF}	Delay from LE to Q, H to L		500	ns	

Input and Output Equivalent Circuits



Switching Waveforms



Recommended Operating Conditions

(over 0 to 70°C for commercial temperature range and -55°C to 125°C for military)

Symbol	Parameter	Min	Max	Units	Comments
V_{DD}	Logic Voltage Supply	4.5	5.5	V	
V_{PP}	High Voltage Supply	8.0	80	V	HV8308 and HV8408
V_{IH}	Input HIGH Voltage	V_{DD}-0.5	V_{DD}	V	
V_{IL}	Input LOW Voltage	0	0.5	V	
f_{CLK}	Clock Frequency	0	8	MHz	

Note:

Power-up sequence should be the following:

1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

5. V_{PP} is not allowed to float during operation.
6. The V_{PP} should not drop below V_{DD} during operations.

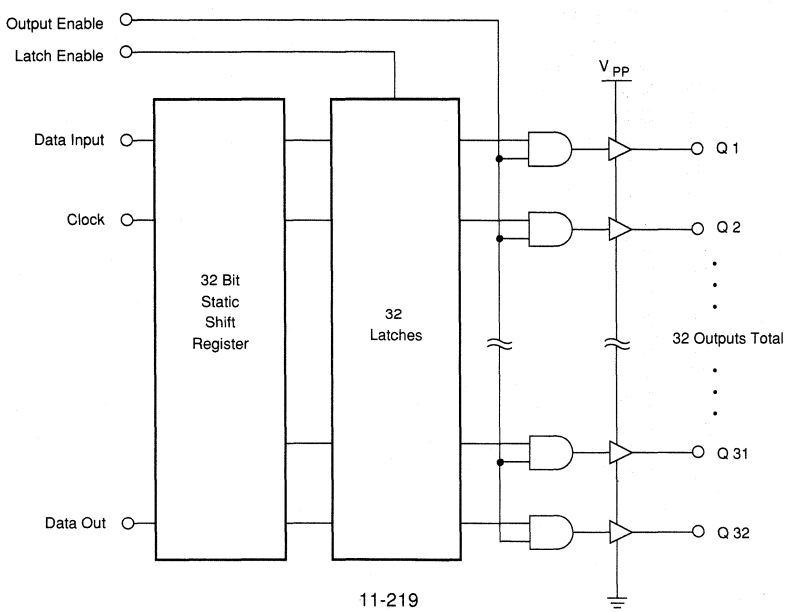
Function Tables

Data Input	CLK*	Data Output
H	↑	H
L	↑	L
X	No ↑	No Change

* ↑ = LOW-to-HIGH level transition

Data Input	LE	OE	Q Output
X	X	L	All Q = LOW
X	L	H	Previous Latched Data
H	H	H	H
L	H	H	L

Functional Block Diagram



Pin Configuration

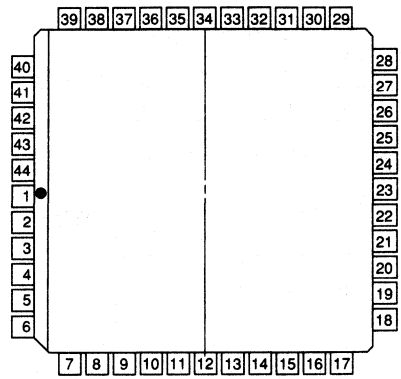
HV83
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	Q 17	23	GND
2	Q 16	24	V_{PP}
3	Q 15	25	V_{DD}
4	Q 14	26	Latch Enable
5	Q 13	27	Data In
6	Q 12	28	Output Enable
7	Q 11	29	N/C
8	Q 10	30	Q 32
9	Q 9	31	Q 31
10	Q 8	32	Q 30
11	Q 7	33	Q 29
12	Q 6	34	Q 28
13	Q 5	35	Q 27
14	Q 4	36	Q 26
15	Q 3	37	Q 25
16	Q 2	38	Q 24
17	Q 1	39	Q 23
18	Data Out	40	Q 22
19	N/C	41	Q 21
20	N/C	42	Q 20
21	N/C	43	Q 19
22	Clock	44	Q 18

HV84
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	Q 16	23	GND
2	Q 17	24	V_{PP}
3	Q 18	25	V_{DD}
4	Q 19	26	Latch Enable
5	Q 20	27	Data In
6	Q 21	28	Output Enable
7	Q 22	29	N/C
8	Q 23	30	Q 1
9	Q 24	31	Q 2
10	Q 25	32	Q 3
11	Q 26	33	Q 4
12	Q 27	34	Q 5
13	Q 28	35	Q 6
14	Q 29	36	Q 7
15	Q 30	37	Q 8
16	Q 31	38	Q 9
17	Q 32	39	Q 10
18	Data Out	40	Q 11
19	N/C	41	Q 12
20	N/C	42	Q 13
21	N/C	43	Q 14
22	Clock	44	Q 15

Package Outline



top view

44-pin J-lead Package

32-Channel Serial To Parallel Converter With High Voltage Push-Pull Outputs

Ordering Information

Device	Package Options		
	44 J-Lead Quad Ceramic Chip Carrier	44 J-Lead Quad Plastic Chip Carrier	Die in waffle pack
HV87	HV8708DJ	HV8708PJ	HV8708X
HV88	HV8808DJ	HV8808PJ	HV8808X

Features

- ☐ Processed with HVCMOS® technology
- ☐ 5V CMOS compatible outputs
- ☐ Output voltages up to 80V
- ☐ Low power level shifting
- ☐ Source/sink current minimum 20mA
- ☐ Shift register speed 8MHz
- ☐ Latched data outputs
- ☐ Forward and reverse shifting options
- ☐ Diode to V_{PP} allows efficient power recovery

Absolute Maximum Ratings[1]

Supply voltage, V_{DD}[2]		-0.5V to +7V
Output voltage, V_{PP}		-0.5V to +80V
Logic input levels[2]		-0.5V to V_{DD} +0.5V
Ground currrent[3]		1.5A
Continuous total power dissipation[4]	Ceramic	1500mW
	Plastic	1200mW
Operating temperature range	Industrial	-40°C to +85°C
	Commerical	0°C to +70°C
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. Device will survive (but operation may not be specified or guaranteed) at these extremes.
2. All voltages are referenced to GND.
3. Duty cycle is limited by the total power dissipated in the package.
4. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

General Description

The HV87 and HV88 are low-voltage serial to high-voltage parallel converters wtih push-pull outputs.These devices have been designed for use as drivers for AC-electroluminescent displays. They can also be used in any application requiring multiple output high-voltage current sourcing and sinking capabilities such as driving plasma panels, vacuum fluorescent displays, or large matrix LCD displays. The inputs are fully CMOS compatible.

These devices consist of a 32-bit shift register, 32 latches, and control logic to perform the polarity select and blanking of the outputs. HVout1 is connected to the first stage of the shift register through the polarity and blanking logic. Data is shifted through the shift register on the logic low to high transition of the clock. The HV87 shifts data in the rclockwise direction when viewed from the top of the package and the HV88 shifts in the counterclockwise direction. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register ($HV_{OUT}32$). Operation of the shift register is not affected by the $\overline{LE}$ (latch enable), $\overline{BL}$ (blanking), or the $\overline{POL}$ (polarity) inputs. Transfer of data from the shift register to the latch occurs when the $\overline{LE}$ (latch enable) input is high. The data in the latch is stored when $\overline{LE}$ is low.

Electrical Characteristics (over recommended operating conditions unless noted)

DC Characteristics

Symbol	Parameter		Min	Max	Units	Conditions
I_{DD}	V_{DD} supply current			15	mA	$V_{DD} = V_{DD}$ max f_{CLK} = 8MHz
I_{PP}	High voltage supply current			100	µA	Outputs high
				100	µA	Outputs low
I_{DDQ}	Quiescent V_{DD} supply current			0.5	mA	All $V_{IN} = V_{SS}$ or V_{DD}
V_{OH}	High-level output	Q	52		V	I_O= -20mA
		Data out	4.5		V	I_O= -100µA
V_{OL}	Low-level output	Q		8	V	I_O= 20mA
		Data out		0.5	V	I_O= 100µA
I_{IH}	High-level logic input current			1	µA	$V_{IH} = V_{DD}$
I_{IL}	Low-level logic input current			-1	µA	V_{IL} = 0V

AC Characteristics (V_{DD} = 5V, T_C = 25°C)

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock frequency		8	MHz	
t_W	Clock width high or low	62		ns	
t_{SU}	Data set-up time before clock rises	25		ns	
t_H	Data hold time after clock rises	10		ns	
t_{ON}, t_{OFF}	Time from latch enable to HV_{OUT}		500	ns	
t_{DHL}	Delay time clock to data high to low		100	ns	C_L = 15pF
t_{DLH}	Delay time clock to data low to high		100	ns	C_L = 15pF
t_{DLE}	Delay time clock to $\overline{LE}$ low to high	50		ns	
t_{WLE}	Width of $\overline{LE}$ pulse	50		ns	
t_{SLE}	$\overline{LE}$ set-up time before clock rises	50		ns	

Recommended Operating Conditions

Symbol	Parameter		Min	Max	Units
V_{DD}	Logic supply voltage		4.5	5.5	V
V_{PP}	Output off voltage		8	75	V
V_{IH}	High-level input voltage		V_{DD} -0.5V	V_{DD}	V
V_{IL}	Low-level input voltage		0	0.5	V
f_{CLK}	Clock frequency			8	MHz
T_A	Operating free-air temperature	Commercial	0	+70	°C

Note:

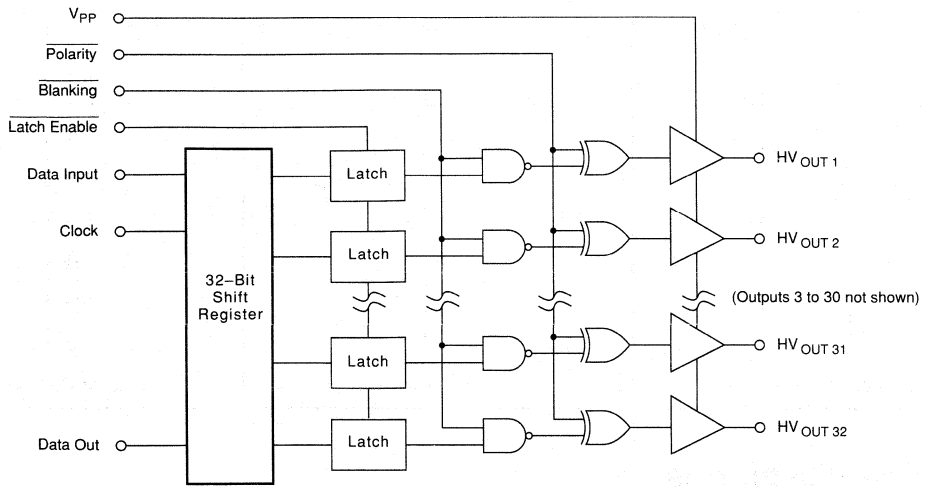
Power-up sequence should be the following:

1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

5. V_{PP} is not allowed to float during operation.
6. The V_{PP} should not drop below V_{DD} during operations.

Functional Block Diagram

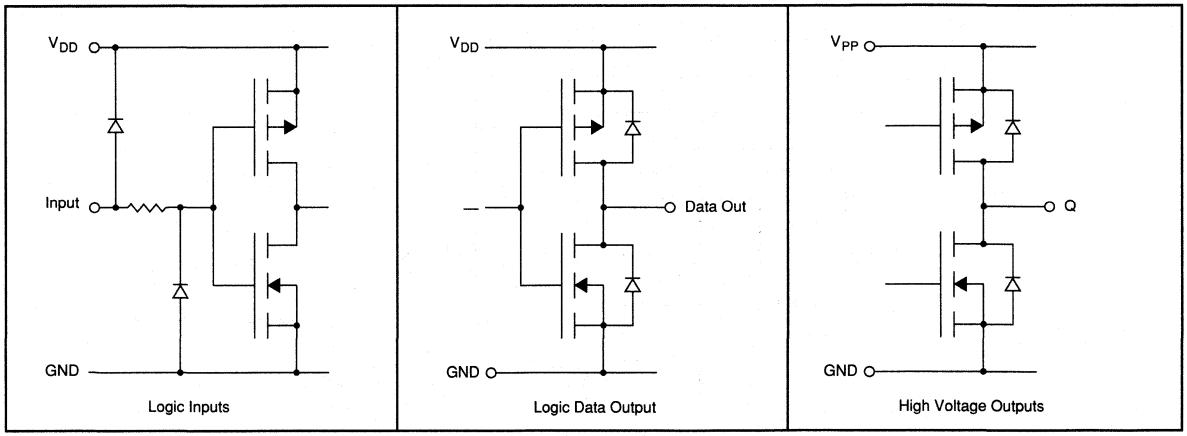


Function Table

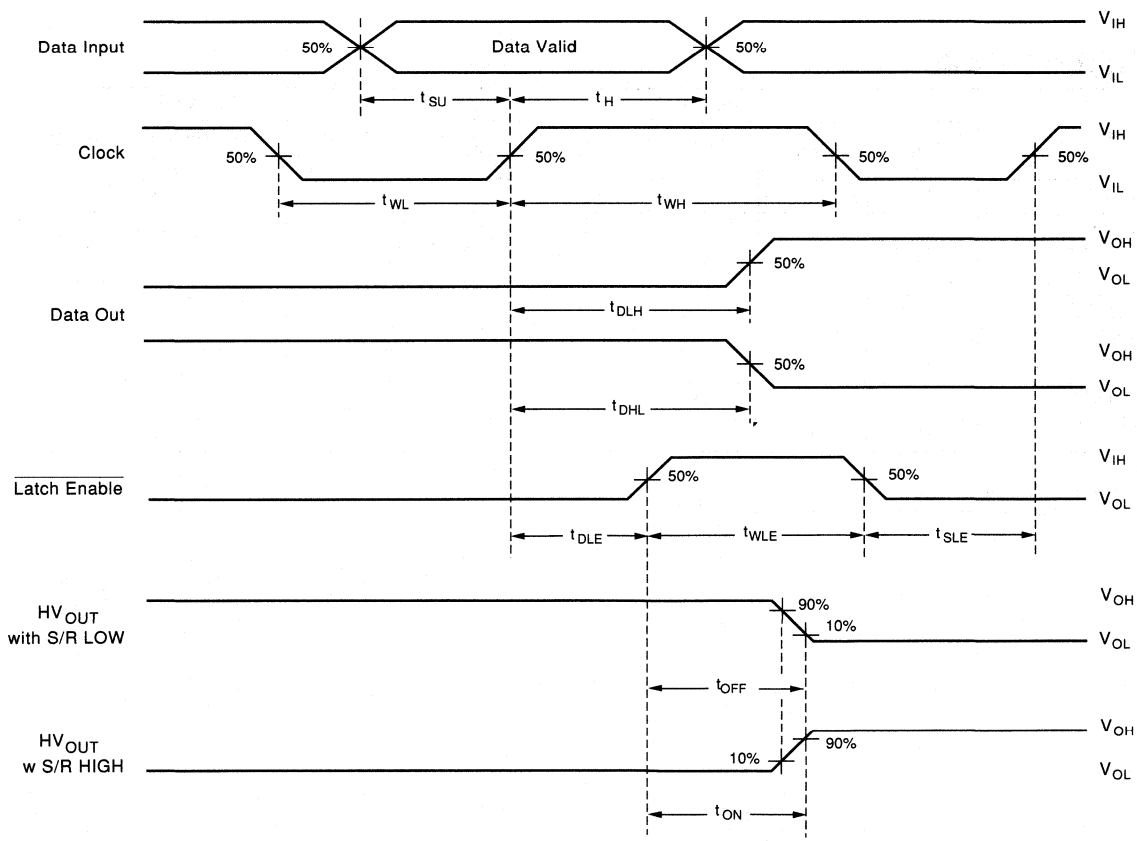
Function	Inputs					Outputs				
	Data	CLK	$\overline{LE}$	$\overline{BL}$	$\overline{POL}$	Shift Reg 1	Shift Reg 2...32	HV Outputs 1	HV Outputs 2...32	Data Out *
All on	X	X	X	L	L	*	*...*	H	H...H	*
All off	X	X	X	L	H	*	*...*	L	L...L	*
Invert mode	X	X	L	H	L	*	*...*	$\overline{*}$	$\overline{*...*}$	*
Load S/R	H or L	↑	L	H	H	H or L	*...*	*	*...*	*
Load latches	X	H or L	↑	H	H	*	*...*	*	*...*	*
	X	H or L	↑	H	L	*	*...*	$\overline{*}$	$\overline{*...*}$	*
Transparent latch mode	L	↑	H	H	H	L	*...*	L	*...*	*
	H	↑	H	H	H	H	*...*	H	*...*	*

Notes:
H = high level, L = low level, X = irrelevant, ↑ = low-to-high transition.
* = dependent on previous stage's state before the last CLK or last LE high,

Input and Output Equivalent Circuits



Switching Waveforms



Pin Configurations

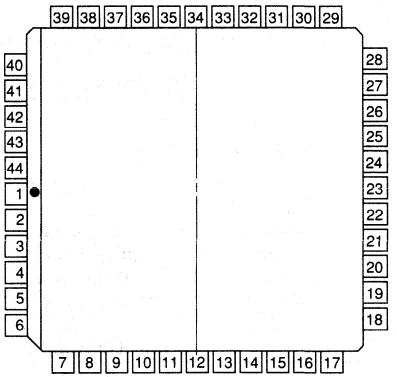
HV87
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 17	23	GND
2	HV_{OUT} 16	24	V_{PP}
3	HV_{OUT} 15	25	V_{DD}
4	HV_{OUT} 14	26	Latch Enable
5	HV_{OUT} 13	27	Data In
6	HV_{OUT} 12	28	Blanking
7	HV_{OUT} 11	29	N/C
8	HV_{OUT} 10	30	HVout 32
9	HV_{OUT} 9	31	HV_{OUT} 31
10	HV_{OUT} 8	32	HV_{OUT} 30
11	HV_{OUT} 7	33	HV_{OUT} 29
12	HV_{OUT} 6	34	HV_{OUT} 28
13	HV_{OUT} 5	35	HV_{OUT} 27
14	HV_{OUT} 4	36	HV_{OUT} 26
15	HV_{OUT} 3	37	HV_{OUT} 25
16	HV_{OUT} 2	38	HV_{OUT} 24
17	HV_{OUT} 1	39	HV_{OUT} 23
18	Data Out	40	HV_{OUT} 22
19	N/C	41	HV_{OUT} 21
20	N/C	42	HV_{OUT} 20
21	$\overline{\text{Polarity}}$	43	HV_{OUT} 19
22	Clock	44	HV_{OUT} 18

HV88
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 16	23	GND
2	HV_{OUT} 17	24	V_{PP}
3	HV_{OUT} 18	25	V_{DD}
4	HV_{OUT} 19	26	Latch Enable
5	HV_{OUT} 20	27	Data In
6	HV_{OUT} 21	28	Blanking
7	HV_{OUT} 22	29	N/C
8	HV_{OUT} 23	30	HV_{OUT} 1
9	HV_{OUT} 24	31	HV_{OUT} 2
10	HV_{OUT} 25	32	HV_{OUT} 3
11	HV_{OUT} 26	33	HV_{OUT} 4
12	HV_{OUT} 27	34	HV_{OUT} 5
13	HV_{OUT} 28	35	HV_{OUT} 6
14	HV_{OUT} 29	36	HV_{OUT} 7
15	HV_{OUT} 30	37	HV_{OUT} 8
16	HV_{OUT} 31	38	HV_{OUT} 9
17	HV_{OUT} 32	39	HV_{OUT} 10
18	Data Out	40	HV_{OUT} 11
19	N/C	41	HV_{OUT} 12
20	N/C	42	HV_{OUT} 13
21	$\overline{\text{Polarity}}$	43	HV_{OUT} 14
22	Clock	44	HV_{OUT} 15

Package Outline



top view

44-pin J-lead Package

32-Channel Serial To Parallel Converter With High Voltage Push-Pull Outputs

Ordering Information

Device	Recommended Operating V_{PP} max	Package Options		
		44 J-Lead Quad Ceramic Chip Carrier	44 J-Lead Quad Plastic Chip Carrier	Dice in waffle pack
HV93	80V	HV9308DJ	HV9308PJ	HV9308X
HV94	80V	HV9408DJ	HV9408PJ	HV9408X

* For Hi-Rel process flows, please refer to page 5-3 in the Databook.

Features

- ☐ Processed with HVCMOS® technology
- ☐ Low power level shifting
- ☐ Shift register speed 8MHz
- ☐ Latched data outputs
- ☐ 5V CMOS compatible inputs
- ☐ Forward and reverse shifting options
- ☐ Diode to V_{PP} allows efficient power recovery
- ☐ 44-lead ceramic surface mount package
- ☐ Hi-Rel processing available

Absolute Maximum Ratings[1]

Supply voltage, V_{DD}[2]		-0.5V to +7V
Supply voltage, V_{PP}		-0.5V to +80V
Logic input levels[2]		-0.5 to V_{DD} + 0.5V
Ground currrent[3]		1.5A
Continuous total power dissipation[4]	Plastic	1200mW
	Ceramic	1500mW
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. Device will survive (but operation may not be specified or guaranteed) at these extrenes.
2. All voltages are referenced to V_{SS}.
3. Duty cycle is limited by the total power dissipated in the package.
4. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

General Description

The HV93 and HV94 are low voltage serial to high voltage parallel converters wtih push-pull outputs. These devices have been designed for use as drivers for AC-electroluminescent displays. They can also be used in any application requiring multiple output high voltage current sourcing and sinking capabilities such as driving plasma panels, vacuum fluorescent, or large matrix LCD displays.

These devices consist of a 32-bit shift register, 32 latches, and control logic to enable outputs. Q1 is connected to the first stage of the shift register through the Output Enable logic. Data is shifted through the shift register on the low to high transition of the clock. The HV94 shifts in the counterclockwise direction when viewed from the top of the package and the HV93 shifts in the clockwise direction. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register (32). Operation of the shift register is not affected by the LE (latch enable) or the OE (output enable) inputs. Transfer of data from the shift register to the latch occurs when the LE input is high. The data in the latch is retained when LE is low.

Electrical Characteristics (V_{PP} = 60V, V_{DD} = 5V, T_A =25°C)

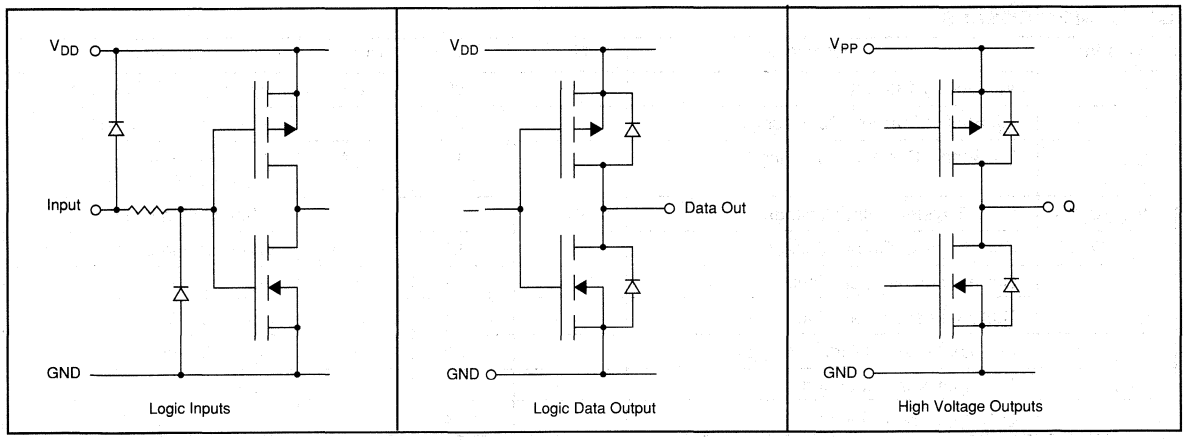
DC Characteristics

Symbol	Parameter	Min	Max	Units	Conditions
I_{PP}	V_{PP} Supply Current		100	µA	Q outputs HIGH to LOW
I_{DDQ}	I_{DD} Supply Current (Quiescent)		100	µA	All inputs = V_{DD} or GND
I_{DD}	I_{DD} Supply Current (Operating)		15	mA	V_{DD} = V_{DD} max, f_{CLK} = 8 MHz
V_{OH} (Data)	Shift Register Output Voltage	V_{DD}-0.5		V	When driving HIGH
V_{OL} (Data)	Shift Register Output Voltage		0.5	V	When driving LOW
I_{IH}	Current Leakage, any input		1	µA	Input = HIGH
I_{IL}	Current Leakage, any input		-1	µA	Input = LOW
V_{OC}	Q Output Clamp Diode Voltage		-1.5	V	I_{OL} = -100mA
V_{OH}	Q Output when Sourcing	52		V	I_{OH} = -20mA, 0 to 70°C
V_{OL}	Q Output when Sinking		4	V	I_{OL} = 5mA, 0 to 70°C

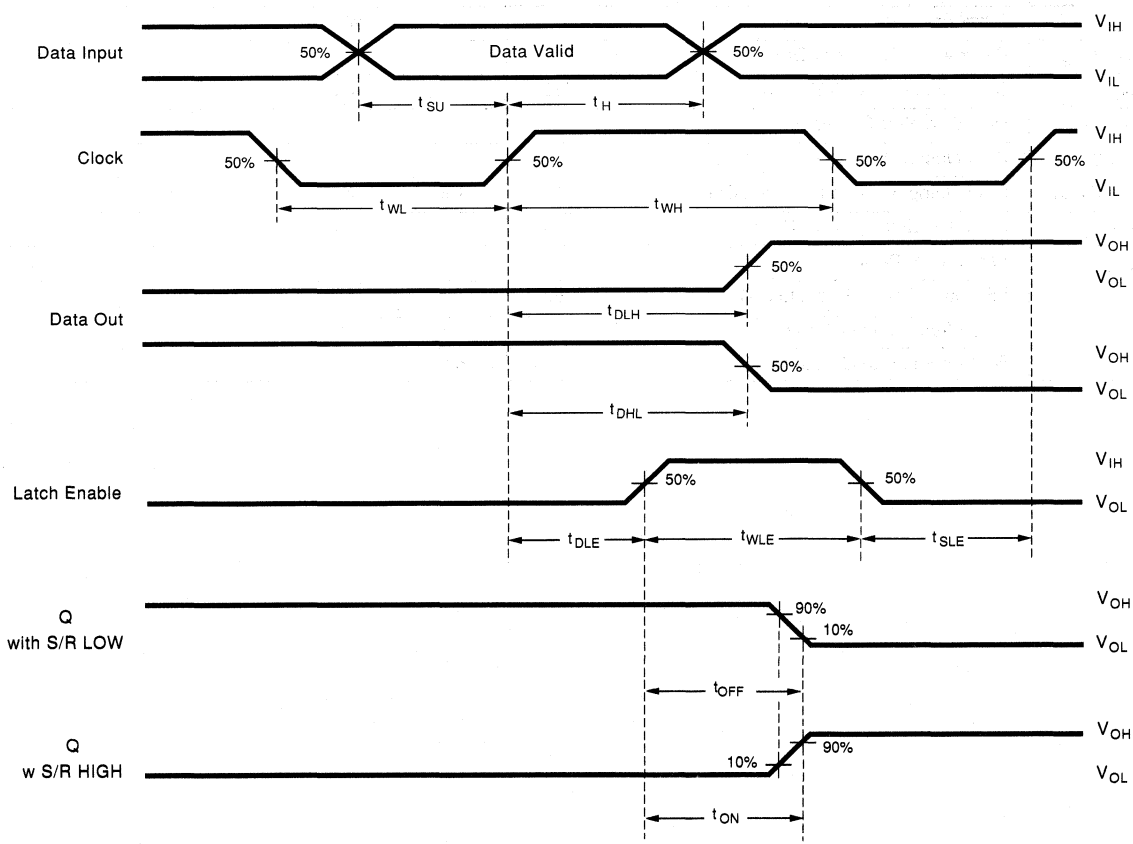
AC Characteristics

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock Frequency		8	MHz	
t_{WL} or t_{WH}	Clock width, HIGH or LOW	62		ns	
t_{SU}	Setup time before CLK rises	25		ns	
t_H	Hold time after CLK rises	10		ns	
t_{DLH} (Data)	Data Output Delay after L to H CLK		100	ns	C_L = 15pF
t_{DHL} (Data)	Data Output Delay after H to L CLK		100	ns	C_L = 15pF
t_{DLE}	LE Delay after L to H CLK	50		ns	
t_{WLE}	Width of LE Pulse	50		ns	
t_{SLE}	LE Setup Time before L to H CLK	50		ns	
t_{ON}	Delay from LE to Q, L to H		500	ns	
t_{OFF}	Delay from LE to Q, H to L		500	ns	

Input and Output Equivalent Circuits



Switching Waveforms



Recommended Operating Conditions

(over 0 to 70°C for commercial temperature range and -55°C to 125°C for military)

Symbol	Parameter	Min	Max	Units	Comments
V_{DD}	Logic Voltage Supply	4.5	5.5	V	
V_{PP}	High Voltage Supply	8.0	80	V	HV9308 and HV9408
V_{IH}	Input HIGH Voltage	V_{DD}-0.5	V_{DD}	V	
V_{IL}	Input LOW Voltage	0	0.5	V	
f_{CLK}	Clock Frequency	0	8	MHz	

Note:

Power-up sequence should be the following:

1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

5. The V_{PP} should not drop below V_{DD} during operations.

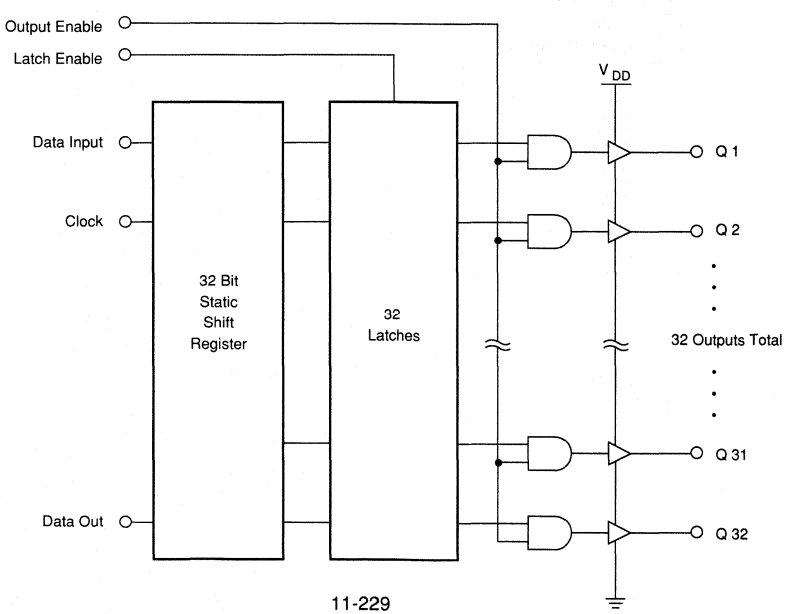
Function Tables

Data Input	CLK*	Data Output
H	⎍	H
L	⎍	L
X	No ⎍	No Change

* ⎍ = LOW-to-HIGH level transition

Data Input	LE	OE	Q Output
X	X	L	All Q = LOW
X	L	H	Previous Latched Data
H	H	H	H
L	H	H	L

Functional Block Diagram



Pin Configuration

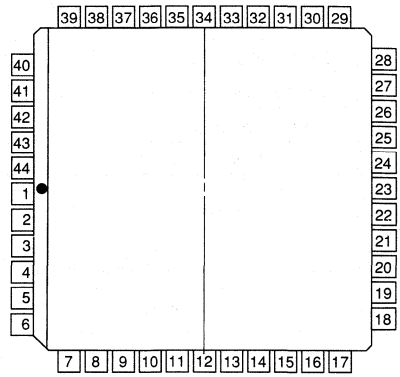
HV93
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	Q 17	23	GND
2	Q 16	24	V_{PP}
3	Q 15	25	V_{DD}
4	Q 14	26	Latch Enable
5	Q 13	27	Data In
6	Q 12	28	Output Enable
7	Q 11	29	N/C
8	Q 10	30	Q 32
9	Q 9	31	Q 31
10	Q 8	32	Q 30
11	Q 7	33	Q 29
12	Q 6	34	Q 28
13	Q 5	35	Q 27
14	Q 4	36	Q 26
15	Q 3	37	Q 25
16	Q 2	38	Q 24
17	Q 1	39	Q 23
18	Data Out	40	Q 22
19	N/C	41	Q 21
20	N/C	42	Q 20
21	N/C	43	Q 19
22	Clock	44	Q 18

HV94
44 Pin J-Lead Package

Pin	Function	Pin	Function
1	Q 16	23	GND
2	Q 17	24	V_{PP}
3	Q 18	25	V_{DD}
4	Q 19	26	Latch Enable
5	Q 20	27	Data In
6	Q 21	28	Output Enable
7	Q 22	29	N/C
8	Q 23	30	Q 1
9	Q 24	31	Q 2
10	Q 25	32	Q 3
11	Q 26	33	Q 4
12	Q 27	34	Q 5
13	Q 28	35	Q 6
14	Q 29	36	Q 7
15	Q 30	37	Q 8
16	Q 31	38	Q 9
17	Q 32	39	Q 10
18	Data Out	40	Q 11
19	N/C	41	Q 12
20	N/C	42	Q 13
21	N/C	43	Q 14
22	Clock	44	Q 15

Package Outline



top view

44-pin J-lead Package

32-Channel Serial To Parallel Converter With High Voltage Push-Pull Outputs

Ordering Information

Device	Package Options		
	44 J-Lead Quad Ceramic Chip Carrier	44 J-Lead Quad Plastic Chip Carrier	Die in waffle pack
HV97	HV9708DJ	HV9708PJ	HV9708X
HV98	HV9808DJ	HV9808PJ	HV9808X

* For Hi-Rel process flows, refer to page 5-3 of the Databook.

Features

- ☐ Processed with HVCMOS® technology
- ☐ Output voltages up to 80V
- ☐ Low power level shifting
- ☐ Shift register speed 8MHz
- ☐ Latched data outputs
- ☐ Forward and reverse shifting options
- ☐ Diode to V_{PP} allows efficient power recovery
- ☐ 5V CMOS compatible inputs
- ☐ Hi-Rel processing available

Absolute Maximum Ratings[1]

Supply voltage, V_{DD}[2]		-0.5V to +7V
Output voltage, V_{PP}		V_{DD} to +80V
Logic input levels[2]		-0.5V to V_{DD} +0.5V
Ground currrent[3]		1.5A
Continuous total power dissipation[4]	Ceramic	1500mW
	Plastic	1200mW
Storage temperature range		-65°C to +150°C
Lead temperature 1.6mm (1/16 inch) from case for 10 seconds		260°C

Notes:
1. Device will survive (but operation may not be specified or guaranteed) at these extremes.
2. All voltages are referenced to GND.
3. Duty cycle is limited by the total power dissipated in the package.
4. For operation above 25°C ambient, derate linearly to 70°C at 12mW/°C.

General Description

The HV97 and HV98 are low-voltage serial to high-voltage parallel converters wtih push-pull outputs.These devices have been designed for use as drivers for AC-electroluminescent displays. They can also be used in any application requiring multiple output high-voltage current sourcing and sinking capabilities such as driving plasma panels, vacuum fluorescent displays, or large matrix LCD displays. The inputs are fully CMOS compatible.

These devices consist of a 32-bit shift register, 32 latches, and control logic to perform the polarity select and blanking of the outputs. HVout1 is connected to the first stage of the shift register through the polarity and blanking logic. Data is shifted through the shift register on the logic low to high transition of the clock. The HV97 shifts data in the clockwise direction when viewed from the top of the package and the HV98 shifts in the counterclockwise direction. A data output buffer is provided for cascading devices. This output reflects the current status of the last bit of the shift register (HVout32). Operation of the shift register is not affected by the $\overline{LE}$ (latch enable), $\overline{BL}$ (blanking), or the $\overline{POL}$ (polarity) inputs. Transfer of data from the shift register to the latch occurs when the $\overline{LE}$ (latch enable) input is high. The data in the latch is stored when $\overline{LE}$ is low.

Electrical Characteristics (V_{PP} = 60V, V_{DD} = 5V, T_A =25°C)

DC Characteristics

Symbol	Parameter	Min	Max	Units	Conditions
I_{PP}	V_{PP} Supply Current		100	µA	HV_{OUT} outputs HIGH to LOW
I_{DDQ}	I_{DD} Supply Current (Quiescent)		100	µA	All inputs = V_{DD} or GND
I_{DD}	I_{DD} Supply Current (Operating)		15	mA f_{CLK} = 8 MHz	V_{DD} = V_{DD} max,
V_{OH} (Data)	Shift Register Output Voltage	V_{DD}-0.5		V	When driving HIGH
V_{OL} (Data)	Shift Register Output Voltage		0.5	V	When driving LOW
I_{IH}	Current Leakage, any input		1	µA	Input = HIGH
I_{IL}	Current Leakage, any input		-1	µA	Input = LOW
V_{OC}	HV_{OUT} Output Clamp Diode Voltage		-1.5	V	I_{OL} = 20mA
V_{OH}	HV_{OUT} Output when Sourcing	52		V	I_{OH} = -20mA, 0 to 70°C
V_{OL}	HV_{OUT} Output when Sinking		4	V	I_{OL} = 5mA, 0 to 70°C

AC Characteristics

Symbol	Parameter	Min	Max	Units	Conditions
f_{CLK}	Clock Frequency		8	MHz	
t_{WL} or t_{WH}	Clock width, HIGH or LOW	62		ns	
t_{SU}	Setup time before CLK rises	25		ns	
t_H	Hold time after CLK rises	10		ns	
t_{DLH} (Data)	Data Output Delay after L to H CLK		100	ns	C_L = 15pF
t_{DHL} (Data)	Data Output Delay after H to L CLK		100	ns	C_L = 15pF
t_{DLE}	LE Delay after L to H CLK	50		ns	
t_{WLE}	Width of LE Pulse	50		ns	
t_{SLE}	LE Setup Time before L to H CLK	50		ns	
t_{ON}	Delay from LE to HV_{OUT}, L to H		500	ns	
t_{OFF}	Delay from LE to HV_{OUT}, H to L		500	ns	

Recommended Operating Conditions

(over 0 to 70°C for commercial temperature range and -55°C to 125°C for military)

Symbol	Parameter	Min	Max	Units	Comments
V_{DD}	Logic Voltage Supply	4.5	5.5	V	
V_{PP}	High Voltage Supply	8.0	80	V	
V_{IH}	Input HIGH Voltage	V_{DD}-0.5	V_{DD}	V	
V_{IL}	Input LOW Voltage	0	0.5	V	
f_{CLK}	Clock Frequency	0	8	MHz	

Note:

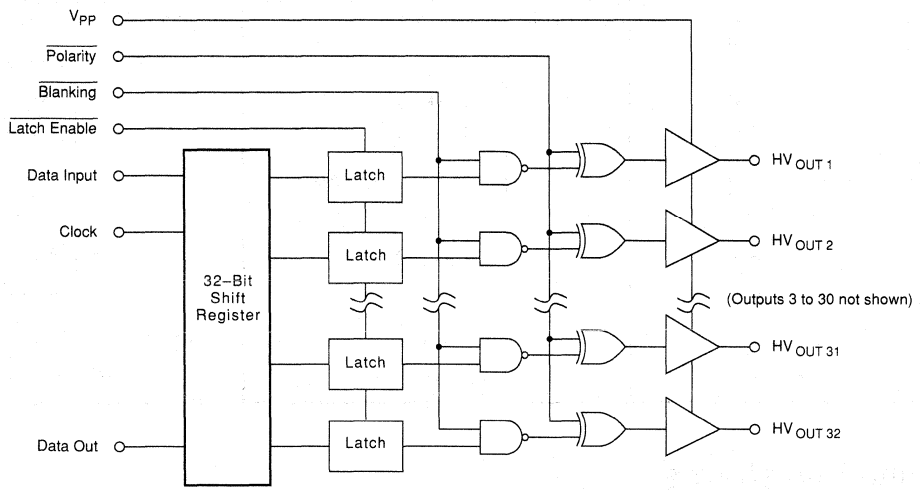
Power-up sequence should be the following:

1. Connect ground.
2. Apply V_{DD}.
3. Set all inputs (Data, CLK, Enable, etc.) to a known state.
4. Apply V_{PP}.

Power-down sequence should be the reverse of the above.

5. The V_{PP} should not drop below V_{DD} or float during operations.

Functional Block Diagram

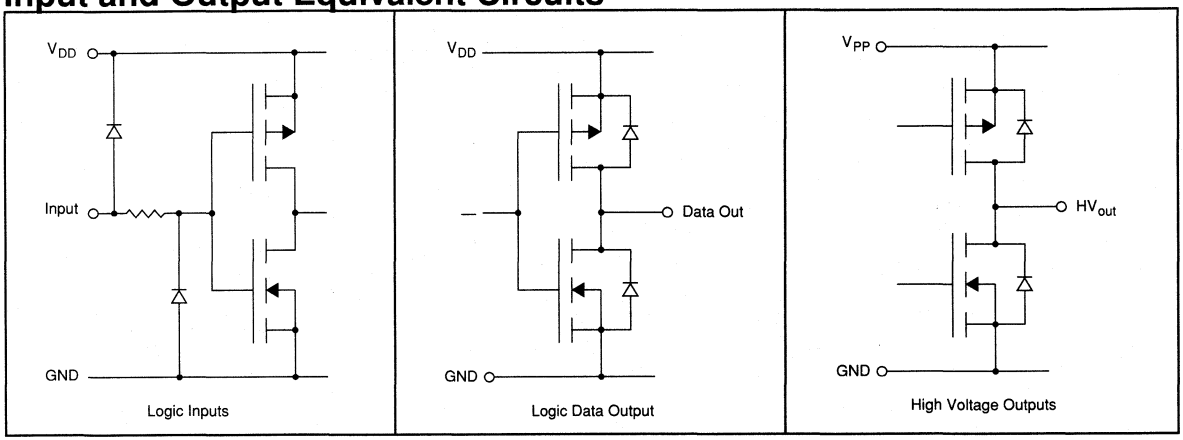


Function Table

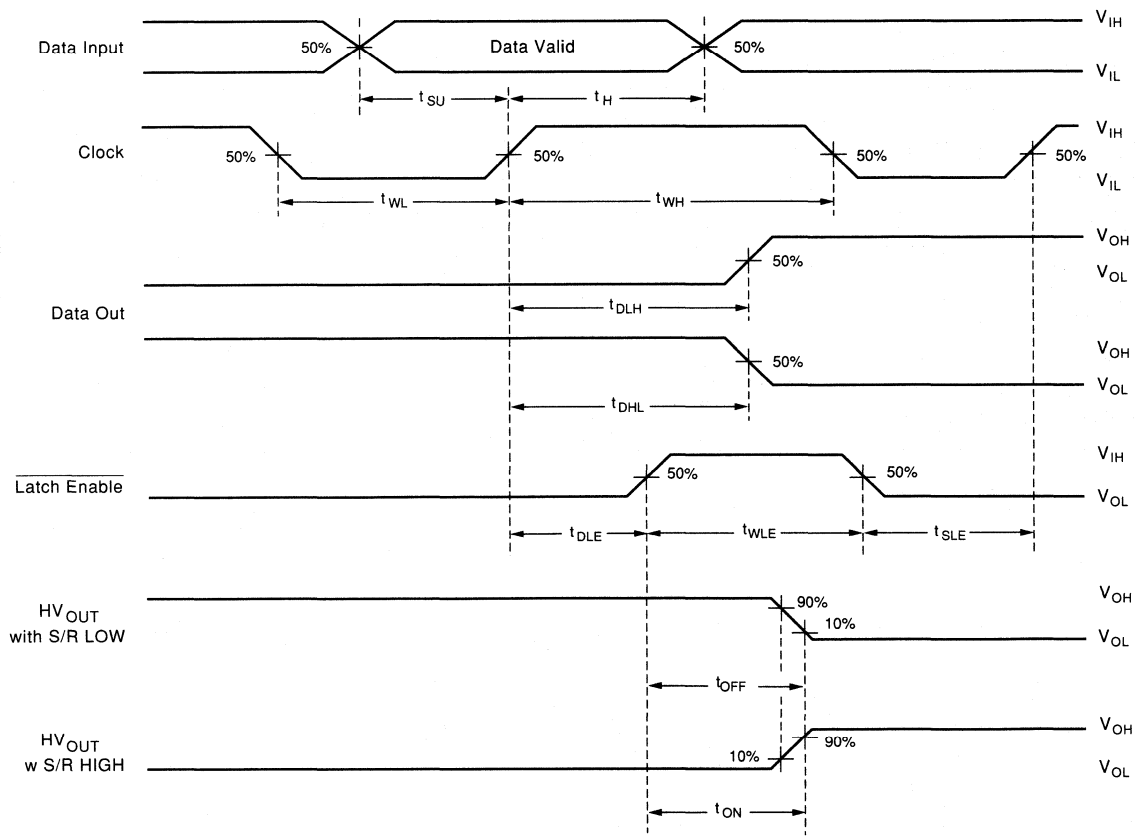
Function	Inputs					Outputs				
						Shift Reg		HV Outputs		Data Out
	Data	CLK	$\overline{LE}$	$\overline{BL}$	$\overline{POL}$	1	2...32	1	2...32	*
All on	X	X	X	L	L	*	*...*	H	H...H	*
All off	X	X	X	L	H	*	*...*	L	L...L	*
Invert mode	X	X	L	H	L	*	*...*	$\overline{*}$	$\overline{*...*}$	*
Load S/R	H or L	↑	L	H	H	H or L	*...*	*	*...*	*
Load latches	X	H or L	↑	H	H	*	*...*	*	*...*	*
	X	H or L	↑	H	L	*	*...*	$\overline{*}$	$\overline{*...*}$	*
Transparent latch mode	L	↑	H	H	H	L	*...*	L	*...*	*
	H	↑	H	H	H	H	*...*	H	*...*	*

Notes:
H = high level, L = low level, X = irrelevant, ↑ = low-to-high transition.
* = dependent on previous stage's state before the last CLK or last $\overline{LE}$ high,

Input and Output Equivalent Circuits



Switching Waveforms



Pin Configurations

HV97

44 Pin J-Lead Package

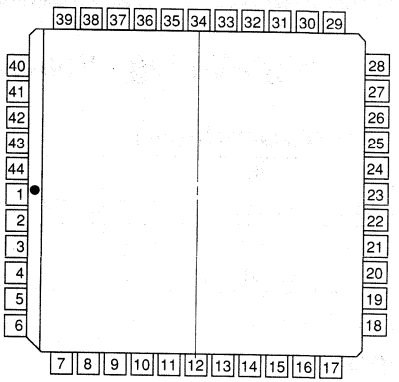
Pin	Function	Pin	Function
1	HV_{OUT} 17	23	GND
2	HV_{OUT} 16	24	V_{PP}
3	HV_{OUT} 15	25	V_{DD}
4	HV_{OUT} 14	26	Latch Enable
5	HV_{OUT} 13	27	Data In
6	HV_{OUT} 12	28	Blanking
7	HV_{OUT} 11	29	N/C
8	HV_{OUT} 10	30	HVout 32
9	HV_{OUT} 9	31	HV_{OUT} 31
10	HV_{OUT} 8	32	HV_{OUT} 30
11	HV_{OUT} 7	33	HV_{OUT} 29
12	HV_{OUT} 6	34	HV_{OUT} 28
13	HV_{OUT} 5	35	HV_{OUT} 27
14	HV_{OUT} 4	36	HV_{OUT} 26
15	HV_{OUT} 3	37	HV_{OUT} 25
16	HV_{OUT} 2	38	HV_{OUT} 24
17	HV_{OUT} 1	39	HV_{OUT} 23
18	Data Out	40	HV_{OUT} 22
19	N/C	41	HV_{OUT} 21
20	N/C	42	HV_{OUT} 20
21	Polarity	43	HV_{OUT} 19
22	Clock	44	HV_{OUT} 18

HV98

44 Pin J-Lead Package

Pin	Function	Pin	Function
1	HV_{OUT} 16	23	GND
2	HV_{OUT} 17	24	V_{PP}
3	HV_{OUT} 18	25	V_{DD}
4	HV_{OUT} 19	26	Latch Enable
5	HV_{OUT} 20	27	Data In
6	HV_{OUT} 21	28	Blanking
7	HV_{OUT} 22	29	N/C
8	HV_{OUT} 23	30	HV_{OUT} 1
9	HV_{OUT} 24	31	HV_{OUT} 2
10	HV_{OUT} 25	32	HV_{OUT} 3
11	HV_{OUT} 26	33	HV_{OUT} 4
12	HV_{OUT} 27	34	HV_{OUT} 5
13	HV_{OUT} 28	35	HV_{OUT} 6
14	HV_{OUT} 29	36	HV_{OUT} 7
15	HV_{OUT} 30	37	HV_{OUT} 8
16	HV_{OUT} 31	38	HV_{OUT} 9
17	HV_{OUT} 32	39	HV_{OUT} 10
18	Data Out	40	HV_{OUT} 11
19	N/C	41	HV_{OUT} 12
20	N/C	42	HV_{OUT} 13
21	$\overline{\text{Polarity}}$	43	HV_{OUT} 14
22	Clock	44	HV_{OUT} 15

Package Outline



top view

44-pin J-lead Package

Preliminary

High-Voltage Switchmode Controllers with MOSFET

Ordering Information

$+V_{IN}$		Feedback	Package Options		
Min	Max	Voltage	14-Pin Plastic DIP	14-Pin Ceramic DIP	20-PinPlastic PLCC
10V	70V	±1%	HV9100P	HV9100C	HV9100PJ
		±10%	HV9101P	HV9101C	HV9101PJ

Features

- ☐ 10 to 70V input range
- ☐ 150V, 5Ω output MOSFET
- ☐ Current-Mode Control
- ☐ High Efficiency
- ☐ Up to 1MHz Internal Oscillator
- ☐ Internal Start-up Circuit

Applications

- ☐ DC/DC Converters
- ☐ Distributed Power Systems
- ☐ ISDN Equipment
- ☐ PBX Systems
- ☐ Modems

Absolute Maximum Ratings

$+V_{IN}$, Input Voltage	70V
V_{DS}	150V
V_{CC}, Logic Voltage	15.0V
Logic Input Voltage	-0.3V to V_{CC}+0.3V
Linear Input, FB and Sense	-0.3V to 7.0V
I_D (Peak)	2.5A
Storage Temperature	-65°C to 150°C
Power Dissipation, Plastic	750mW
Power Dissipation, Ceramic	1W

General Description

The Supertex HV9100 and HV9101 are high voltage switch-mode controllers with an on-board MOSFET, designed to drive inductive loads for high efficient DC to DC conversion. High voltage inputs utilizing HVCMOS technology allow a wide range of input voltage, 10 to 70V regulated or unregulated DC power source.

The internal oscillator frequency can be adjusted via an external resistor or synchronized to an external clock. The low capacitance N-channel MOSFET at the output stage allows fast switching. Maximum rated sink current is 2.5A. Other features are current mode PWM, pre-regulator/start-up, error amplifier, shut down during fault, and reset input.

Applications include DC/DC converters, variable speed motor drives, ISDN and PBX equipment, modems, and distributed power systems.

Electrical Characteristics

(V_{CC} = 10V, $+V_{IN}$ = 48V, Discharge = $-V_{IN}$ = OV, R_{BIAS}=390KΩ, R_{OSC}=330KΩ,T_A=25°C, Unless Otherwise Specified)

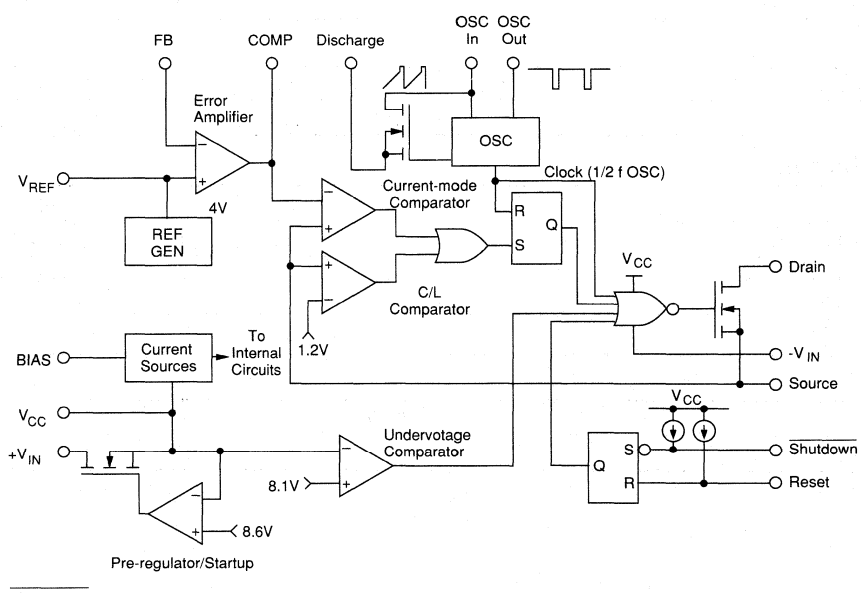
Symbol	Parameters		Min	Typ	Max	Unit	Conditions
Reference							
V_{REF}	Output Voltage		3.92	4.0	4.08	V	R_L = 10MΩ
Z_{OUT}	Output Impedance		15	30	45	KΩ	
I_{SHORT}	Short Circuit Current		70	100	130	µA	V_{REF} = $-V_{IN}$
ΔV_{REF}	Change in V_{REF} with Temperature			1		mV/°C	
Oscillator							
f_{OSC}	Oscillator Frequency		1	3		MHz	R_{OSC} = 0Ω
Δf_{OSC}	Initial Accuracy		80	100	120	KHz	
V_{OSC}	Voltage Stability			±3		%	9.5V < V_{CC} <13.5V
K	Temperature Coefficient			500		ppm/°C	
Error Amplifier							
V_{FB}	Feedback Voltage	HV9100	3.96	4.00	4.04	V	V_{FB} Shorted to Comp
		HV9101	3.60	4.00	4.40		
I_{IN}	Input Bias Current			25	500	nA	V_{FB} = 4.0V
V_{OS}	Input Offset Voltage			15	40	mV	
A_{VOL}	Open Loop Voltage Gain		60	80		dB	
GB	Unity Gain Bandwidth			1.0		MHz	
Z_{OUT}	Output Impedance			500		Ω	
I_{SOURCE}	Output Source Current		1.4	2.0		mA	V_{FB} = 3.4V
I_{SINK}	Output Sink Current		0.12	0.15		mA	V_{FB} = 4.5V
PSRR	Power Supply Rejection			70		dB	9.5V < V_{CC} < 13.5V
Current Limit							
V_{SOURCE}	Threshold Voltage		1.0	1.2	1.4	V	V_{FB} = 0V, R_L = 100Ω
t_d	Delay to Output			150	200	ns	V_{SOURCE} = 1.4V, R_L =100Ω
Pre-Regulator/Startup							
$+V_{IN}$	Input Voltage				70	V	I_{IN} = 10uA
$+I_{IN}$	Input Leakage Current				10	µA	V_{CC}>9.4V
V_{TH}	VCC Pre-regulator Turn-off Threshold Voltage		7.8	8.6	9.4	V	I_{PREREG} = 10µA
V_{LOCK}	Undervoltage Lockout		7.0	8.1	8.9	V	R_L = 100Ω
Supply							
I_{CC}	Supply Current			0.60	1.0	mA	
I_{BIAS}	Bias Current			15		µA	

Electrical Characteristics (Continued)

(V_{CC} = 10V, $+V_{IN}$ = 48V, Discharge = $-V_{IN}$ = 0V, R_{BIAS} = 390KΩ, R_{OSC} = 330KΩ,T_A = 25°C, unless otherwise specified)

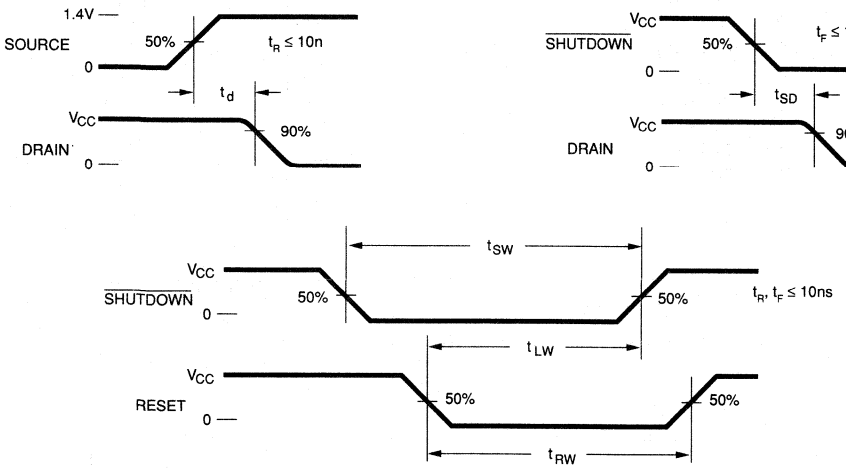
Symbol	Parameters	Min	Typ	Max	Unit	Conditions
Logic						
t_{SD}	$\overline{\text{Shutdown}}$ Delay		50	100	ns	$V_{SOURCE} = -V_{IN}$
t_{SW}	$\overline{\text{Shutdown}}$ Pulse Width	50			ns	
t_{RW}	RESET Pulse Width	50			ns	
t_{LW}	Latching Pulse Width	25			ns	
V_{IL}	Input Low Voltage			2.0	V	
V_{IH}	Input High Voltage	8.0			V	
I_{IH}	Input High Current		1	5	uA	V_{IN} = 10V
I_{IL}	Input Low Current		-25	-35	uA	V_{IN} = 0V
MOSFET Switch						
BV_{DSS}	Breakdown Voltage	150	180		V	V_{SOURCE} = $\overline{\text{Shutdown}}$ = OV, I_D = 100μA
R_{ON}	Drain-to-Source On-resistance		3.0	5.0	Ω	V_{SOURCE} = OV, I_D = 100mA
I_{DSS}	Drain Off Leakage Current			10	μA	V_{SOURCE} = $\overline{\text{Shutdown}}$ = OV, V_{DRAIN} = 100V
C_{DS}	Drain Capacitance		250		pF	

Functional Block Diagram



*Consult factory

Switching Waveforms



Truth Table

$\overline{\text{Shutdown}}$	Reset	Output
H	H	Normal Operation
H	H → L	Normal Operation, No Change
L	H	Off, Not Latched
L	L	Off, Latched
L → H	L	Off, Latched, No Change

Pin Configuration

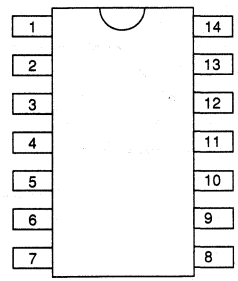
14-Pin SOIC/DIP Package

Pin	Function	Pin	Function
1	BIAS	8	OSC In
2	$+V_{IN}$	9	Discharge
3	Drain	10	V_{REF}
4	Source	11	$\overline{\text{Shutdown}}$
5	$-V_{IN}$	12	Reset
6	V_{CC}	13	COMP
7	OSC Out	14	FB

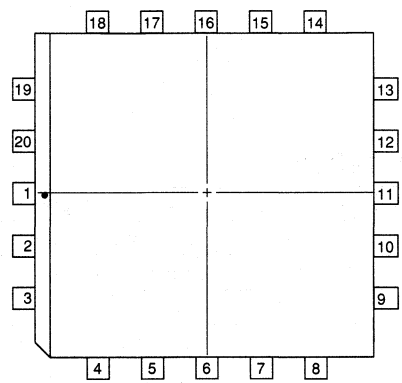
20-Pin J-Lead Package

Pin	Function	Pin	Function
1	NC	11	OSC In
2	BIAS	12	Discharge
3	$+V_{IN}$	13	NC
4	NC	14	V_{REF}
5	Drain	15	NC
6	NC	16	$\overline{\text{Shutdown}}$
7	Source	17	Reset
8	$-V_{IN}$	18	COMP
9	V_{CC}	19	NC
10	OSC Out	20	FB

Package Outline



14 Pin SOIC/DIP Package



top view

20-pin PJ Package

Preliminary

High-Voltage Switchmode Controllers

Ordering Information

$+V_{IN}$		Feedback		Package Options		
Min	Max	Voltage	Package Pins	Plastic DIP	Ceramic DIP	Plastic PLCC
10V	120V	±1%	14	HV9110P	HV9110C	—
			20	—	—	HV9110PJ
10V	120V	±10%	14	HV9111P	HV9111C	—
			20	—	—	HV9111PJ
10V	450V	±2%	16	HV9120P	HV9120C	—
			20	—	—	HV9120PJ

Features

- ☐ 10 to 450V input range
- ☐ Current-Mode Control
- ☐ High-Speed, Push-Pull Output Drive
- ☐ High Efficiency
- ☐ Up to 1MHz Internal Oscillator
- ☐ Internal Start-up Circuit

Applications

- ☐ DC/DC Converters
- ☐ Distributed Power Systems
- ☐ ISDN Equipment
- ☐ PBX Systems
- ☐ Modems

General Description

The Supertex HV9110/HV9111/HV9120 are high voltage switchmode controllers are designed to be coupled directly to a power MOSFET in a variety of applications. High voltage inputs utilizing HVCMOS technology allow a wide range of input voltage for direct off-line operation.

The internal oscillator frequency can be adjusted via an external resistor or synchronized to an external clock. The push-pull output stage allows fast switching. Maximum rated sink/source current is 125 mA. Other features are current mode PWM, pre-regulator/startup, error amplifier, shut down during fault, and reset input.

Applications include DC/DC converters, variable speed motor drives, ISDN and PBX equipment, modems, and distributed power systems.

Absolute Maximum Ratings

$+V_{IN}$, Input Voltage	HV9110/HV9111	120V
	HV9120	450V
V_{CC}, Logic Voltage		15.0V
Logic Input Voltage		-0.3V to V_{CC}+0.3V
Linear Input, FB and Sense		-0.3V to 7.0V
Continuous Output Current		±125mA
Storage Temperature		-65°C to 150°C
Power Dissipation, Plastic		750mW
Power Dissipation, Ceramic		1W

Electrical Characteristics

(V_{CC} = 10V, $+V_{IN}$ = 48V, $+V_{IN}$ = 300V for HV9120, Discharge = $-V_{IN}$ = OV, R_{BIAS} = 390KΩ, R_{OSC} = 330KΩ,T_A = 25°C, unless otherwise specified)

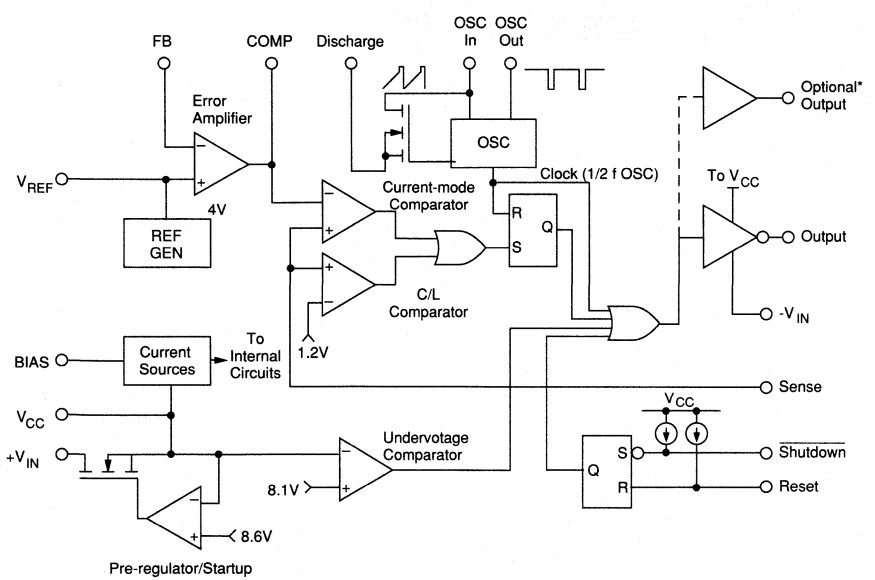
Symbol	Parameters		Min	Typ	Max	Unit	Conditions
Reference							
V_{REF}	Output Voltage		3.92	4.0	4.08	V	R_L = 10MΩ
Z_{OUT}	Output Impedance		15	30	45	KΩ	
I_{SHORT}	Short Circuit Current		70	100	130	µA	V_{REF} = $-V_{IN}$
ΔV_{REF}	Change in V_{REF} with Temperature			1		mV/°C	
Oscillator							
f_{OSC}	Oscillator Frequency		1	3		MHz	R_{OSC} = 0Ω
Δf_{OSC}	Initial Accuracy		80	100	120	KHz	
V_{OSC}	Voltage Stability			±3		%	9.5V < V_{CC} <13.5V
K	Temperature Coefficient			500		ppm/°C	
Error Amplifier							
V_{FB}	Feedback Voltage	HV9111	3.60	4.00	4.40	V	V_{FB} Shorted to Comp
		HV9110	3.96	4.00	4.04		
		HV9120	3.92		4.08		
I_{IN}	Input Bias Current			25	500	nA	V_{FB} = 4.0V
V_{OS}	Input Offset Voltage			15	40	mV	
A_{VOL}	Open Loop Voltage Gain		60	80		dB	
GB	Unity Gain Bandwidth	HV9110/11		1.0		MHz	
		HV9120	1.0	1.5			
Z_{OUT}	Output Impedance			500		Ω	
I_{SOURCE}	Output Source Current		1.4	2.0		mA	V_{FB} = 3.4V
I_{SINK}	Output Sink Current		0.12	0.15		mA	V_{FB} = 4.5V
PSRR	Power Supply Rejection			70		dB	9.5V < V_{CC} < 13.5V
Current Limit							
V_{SOURCE}	Threshold Voltage		1.0	1.2	1.4	V	V_{FB} = 0V
t_d	Delay to Output			150	200	ns	V_{SENSE} = 1.4V
Pre-regulator/Startup							
$+V_{IN}$	Input Voltage	HV9110/11			120	V	I_{IN} = 10uA
		HV9120			450		
$+I_{IN}$	Input Leakage Current				10	µA	V_{CC}>9.4V
V_{TH}	VCC Pre-regulator Turn-off Threshold Voltage		7.8	8.6	9.4	V	I_{PREREG} = 10µA
V_{LOCK}	Undervoltage Lockout		7.0	8.1	8.9	V	I_{OUTPUT} = 1mA
Supply							
I_{CC}	Supply Current	HV9110/11		0.60	1.0	mA	
		HV9120		0.75	1.2		
I_{BIAS}	Bias Current			15		µA	

Electrical Characteristics (Continued)

(V_{CC} = 10V, $+V_{IN}$ = 48V, $+V_{IN}$ = 300V for HV9120, Discharge = $-V_{IN}$ = OV, R_{BIAS}=390KΩ, R_{OSC}=330KΩ,T_A=25°C, unless otherwise specified)

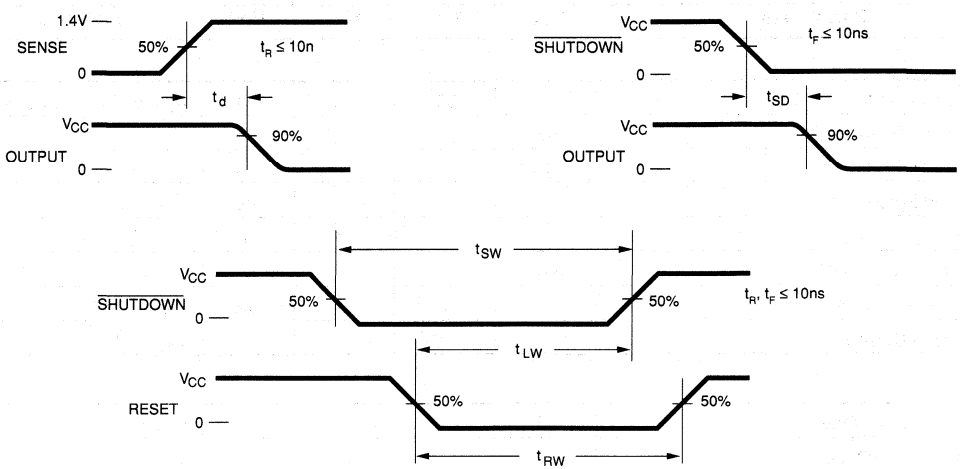
Symbol	Parameters		Min	Typ	Max	Unit	Conditions
Logic							
t_{SD}	$\overline{\text{Shutdown}}$ Delay			50	100	ns	C_L = 500pF, V_{SENSE} = $-V_{IN}$
t_{SW}	$\overline{\text{Shutdown}}$ Pulse Width		50			ns	
t_{RW}	RESET Pulse Width		50			ns	
t_{LW}	Latching Pulse Width		25			ns	
V_{IL}	Input Low Voltage				2.0	V	
V_{IH}	Input High Voltage		8.0			V	
I_{IH}	Input High Current			1	5	uA	V_{IN} = 10V
I_{IL}	Input Low Current			-25	-35	uA	V_{IN} = 0V
Output							
V_{OH}	Output High Voltage		9.9			V	I_{OUT} = 1mA
V_{OL}	Output Low Voltage				0.1		I_{OUT} = -1mA
R_{OUT}	Output Resistance	HV9110/11		20	30	Ω	
		HV9120		20		Ω	
t_R	Rise Time			40	75	ns	C_L = 500pF
t_F	Fall Time			40	75	ns	C_L = 500pF

Functional Block Diagram



*Consult factory

Switching Waveforms



Truth Table

$\overline{\text{Shutdown}}$	Reset	Output
H	H	Normal Operation
H	H → L	Normal Operation, No Change
L	H	Off, Not Latched
L	L	Off, Latched
L → H	L	Off, Latched, No Change

Pin Configuration

14-Pin SOIC/DIP Package

Pin	Function	Pin	Function
1	BIAS	8	OSC In
2	$+V_{IN}$	9	Discharge
3	Sense	10	V_{REF}
4	Output	11	$\overline{\text{Shutdown}}$
5	$-V_{IN}$	12	Reset
6	V_{CC}	13	COMP
7	OSC Out	14	FB

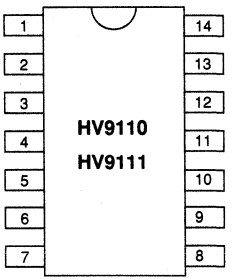
16-Pin DIP Package

Pin	Function	Pin	Function
1	$+V_{IN}$	9	OSC In
2	NC	10	Discharge
3	NC	11	V_{REF}
4	Sense	12	$\overline{\text{Shutdown}}$
5	Output	13	Reset
6	$-V_{IN}$	14	COMP
7	V_{CC}	15	FB
8	OSC Out	16	BIAS

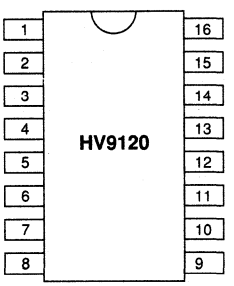
20-Pin J-Lead Package

Pin	Function	Pin	Function
1	NC	11	OSC In
2	BIAS	12	Discharge
3	$+V_{IN}$	13	NC
4	Sense	14	V_{REF}
5	NC	15	NC
6	Output	16	$\overline{\text{Shutdown}}$
7	NC	17	Reset
8	$-V_{IN}$	18	COMP
9	V_{CC}	19	NC
10	OSC Out	20	FB

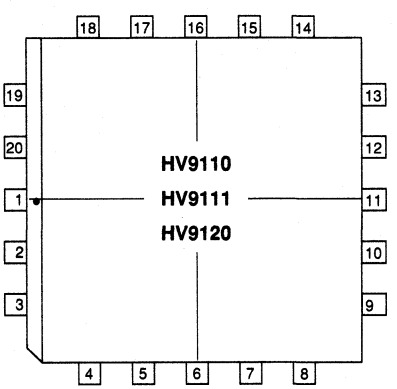
Package Outline



14 Pin SOIC/DIP Package



16-Pin DIP Package



top view

20-pin PJ Package

Programmable Data Coder

Ordering Information

Device	28-Pin Plastic DIP	28-Pin Plastic Quad J Lead	28-Pin SO Gullwing	Die
DC7	DC7P	DC7PJ	DC7WG	DC7X

Features

- ☐ 8 Data Bits (Byte Wide Data)
- ☐ 7 Address Bits (128 Addresses)
- ☐ Manchester Phase Encoding
- ☐ Transmitter/Receiver in one circuit
- ☐ Schmitt Trigger Input for excellent noise rejection
- ☐ Built-in Oscillator using non-critical RC Components
- ☐ Zener Diode to regulate the power supply
- ☐ Low Power, High Noise Immunity CMOS technology
- ☐ Ability to Decode Original Signals
- ☐ Automatic Preamble Generation

Applications

- ☐ Multi-port Computer I/O
- ☐ Smoke & Fire Alarm Control Systems
- ☐ Pocket Pagers
- ☐ Digital Locks
- ☐ Theft Alarm Systems
- ☐ Security Systems
- ☐ Digital Paging Systems
- ☐ Special Identification Code Systems
- ☐ Remote Sensor Data Acquisition Systems
- ☐ Single Channel Digital Transmission of Information

General Description

The DC7 is a single monolithic chip using metal gate CMOS technology for low cost, low power, high yield and high reliability. This dual purpose circuit is capable of working either as an encoder, or decoder of its own transmission, in applications where exclusive recognition of address codes is required in addition to transmission or reception of 8 Data Bits. It will decode 1 of 128 address codes. In the transmit mode, this circuit is capable of generating the possible codes by connecting the Address and Data Inputs to V_{DD} or GND for a "1" or a "0". In the receive mode, this circuit is capable of decoding the transmitted signals and simultaneously making comparisons to the local address code for identification.

Absolute Maximum Ratings

Supply Voltage with respect to GND	6.4V
Operating Temperature	-40°C to +85°C
Storage Temperature	-55°C to +150°C
Zener Current	100mA

Electrical Characteristics

DC Characteristics (V_{DD} = 5.0 ± 5%; GND = 0V; T_A = 25°C)

Symbol	Parameter	Min	Typ (Note 1)	Max	Unit	Conditions
V_{IH}	Input High Voltage	V_{DD} - 0.3		V_{DD} + 0.3	V	"1" INPUT
V_{IL}	Input Low Voltage	GND - 0.3		0.3	V	"0" INPUT
I_{LKC}	Input Leakage Current		0.1	2.0	µA	V_{IN} = 5.0V for pins T/R, SDI
I_{LC}	Input Load Current	2.0	6.0	20.0	µA	V_{IN} = 5.0V for pins RS, A0 - A6, D0 - D7
V_{OH}	Output High Voltage	V_{DD} - 0.3			V	V_{DD} = 4.75V, I_{LOAD} = -100µA
V_{OL}	Output Low Voltage			0.3	V	V_{DD} = 4.75V, I_{LOAD} = 100µA
I_{OH}	Output High Current (Sourcing)	-1.0	-1.5		mA	V_{OH} = V_{DD} - 1.0V
I_{OL}	Output Low Current (Sinking)	1.0	3.0		mA	V_{OL} = 1.0V
V_Z	Zener Voltage	5.5	6.4	7.0	V	I_Z = 10µA (Note 2)
		6.0	6.7	7.5	V	I_Z = 10mA (Note 2)
C_{IN}	Input Capacitance			10	pF	(Note 2)
C_{OUT}	Output Capacitance			10	pF	(Note 2)
I_{DD}	Drain Current			10	µA	V_{DD} = 5.0V, all inputs = GND all outputs floating

Notes:
1. Typical values are those values measured in a production sample at V_{CC} = 5.0V.
2. This parameter is periodcally sampled and is not 100% tested.

AC Characteristics (V_{DD} = 5.0 ± 5%; T_A = 25°C)

Symbol	Parameter	Min	Typ (Note 1)	Max	Unit	Conditions
f_C	Clock Frequency	0		20	kHz	R = 150k, C = 100pF; Clock Period (t_C) = 1/f_c
t_{SDI}	Start Pulse Width	500			ns	
t_{DDO}	DDO Delay from SDI		5		µs	
t_{DC}	Data Clock Pulse Width		.5t_C		sec	
t_{WORD}	Full Cycle Word Length		130t_C		sec	
R_R	Receiver Oscillator Resistor Tolerance from Transmitter Oscillator Resistor		±10		%	
C_R	Receiver Oscillator Capacitor Tolerance from Transmitter Oscillator Capacitor		±10		%	

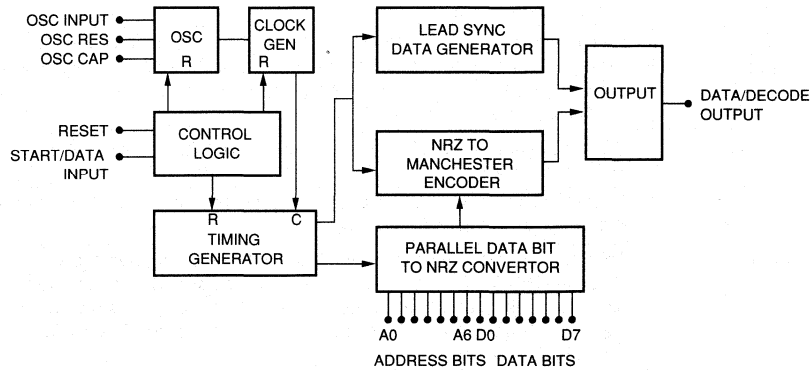
Note:
1. Typical values are those values measured on a production sample at V_{CC} = 5.0V.

Pin Definition

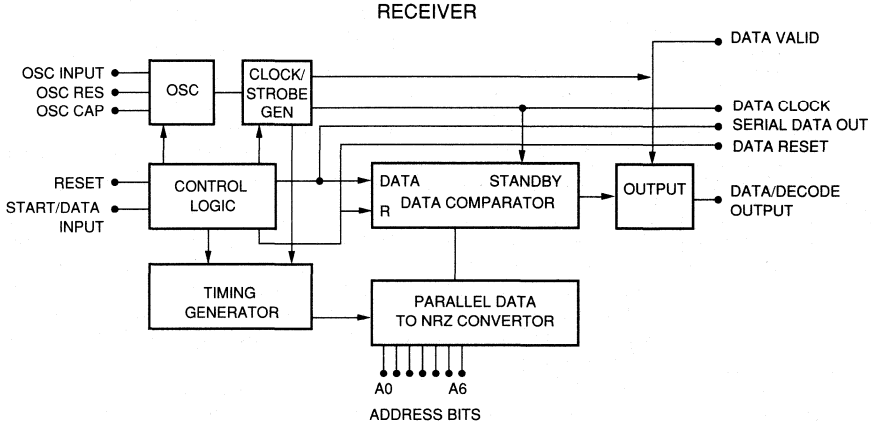
Label	Pin Name	Function
GND	Ground	Supply Potential negative side.
OI	Oscillator Input	This input is to drive the oscillator and is the tie point of the timing resistor (R_T), and the timing capacitor(C_T). It also is connected through a diode to an open drain P-channel device that turns on to V_{DD} when the oscillator is being reset. This input can exceed the power supplies during normal oscillator operation.
OR	Oscillator	Provides phase feedback to the RC timing circuit through the connected timing resistor. Note: This Resistor pin is driven high during oscillator reset.
OC	Oscillator Capacitor	Capacitor connection of RC timing circuit provides phased feedback from the oscillator. This pin is driven low during oscillator reset.
RS	Reset	This input pin may be used to override the data transmission cycle or to inhibit an SDI input. It clears the D/DO to a low state and resets the internal oscillator and data comparison circuits. This pin may be left open (No Connection) when not used, or driven as an input, or an external capacitor (100pF) to V_{DD} may be added for power-up reset. The Reset function is activated when this input is connected to V_{DD}.
S/DI	Start/Data Input	Start/Data input is a dual function pin. It is used to start the oscillator which enables the transmission of the encoded word in the transmit mode. And, in the receive mode, this input receives the serial coded information for processing and comparison.
D/DO	Data/Decode Output	Another dual purpose pin, this pin is the encoded sequence data output in the transmit mode and becomes the decode true output in the receive mode. It indicates that the incoming code has matched the local bit data input address.
A0-A6	Address Inputs	These Inputs provide the parallel Address to be sequentially transmitted. In the receive mode, these inputs become the parallel local Address code for comparison with the incoming data.
D0-D7	Data Bit Inputs	These Inputs provide parallel data to be sequentially transmitted. In the receive mode, these Inputs are not used.
SDO	Serial Data Output	This output signal is a buffered S/DI signal after going through the input Schmitt Trigger, a delay circuit, and is the same polarity as the input and can be used to chain a number of receivers together. This output can be connected to the input of an 8-bit shift register (clocked by the DC pin) in a receiver system where data is to be recovered. This output can be connected to the input of a 16-bit shift register (clocked by the DC pin) in a receiver system where Address and data are to be recovered.
DRS	Data Reset Output	Data Reset can be used in the receive mode to reset an external data shift register since this signal pulse indicates that a new word has just begun processing.
DC	Data Clock Outputs	The Data Clock output may be used in a receive system since it is the recovered data sync pulses. Also, this output can be used to clock an external shift register where data is to be recovered.
DV	Data Valid Output	This output is triggered low at the start of any input and will remain low until a complete word has been processed. Note that this output simply signals that a valid word has been received and not that the code received has matched the local address code.
T/R	Transmit/ Receive	This is a control input to determine the operating mode. A logic high applied to this input puts it in the transmit mode; a logic low puts it in the receive mode.
V_{DD}	V_{DD}	Positive Supply Potential: This circuit contains an on-chip zener of approximately 6.7 volts across the supply terminals.

Block Diagrams

TRANSMITTER



RECEIVER



Operation

General

The DC7 mode of operation is controlled by the Transmit/Receive control input (T/R). When switched from V_{DD} to GND, the circuit will automatically change the oscillator, Start/Data Input, and Data Decoder Output from Transmit to Receive mode.

The DC7 contains an on-chip zener diode to clamp the power supply to around 6.7 volts. The circuit will operate from 4.0 volts to the zener voltage, but operation is recommended at 5 volts ± 5%, or from a regulated power supply in order to stabilize the time constants of the oscillator circuit. In order to use the on-chip zener diode, a current limiting resistor of 1K ohm or greater is required. If pull up resistors are used for the D_1 - D_{15} drivers, the resistors should be tied to a voltage no higher than that on Pin 28 or 6 volts, whichever is lower.

Output drivers are capable of sinking or sourcing 1.0mA minimum at 1.0 volt V_{DS}. All inputs are gate protected to both power supplies by internal diodes. The Address Data Inputs of the DC7 each have pull down resistors to ground so that only a "1" will have to be programmed. This allows the inputs to be programmed by using SPST switches or jumpers to V_{DD} only. The Transmit/Receive input does not have a pull up or pull down resistor. The Start/Data Input also does not have a pull up or pull down resistor, but is applied to a Schmitt Trigger Input circuit to improve noise rejection.

Transmit Function

This function is selected by connecting the Transmit/Receive control input to V_{DD}. This enables the Transmit mode and the circuit to function, as an encoder, sampling the 7 Address and 8 Data Input pin digital information and encoding this parallel data in NRZ format, combining it with the clock in Manchester Code (Phase Encoded) and presenting it to the D/DO pin for transmission. (usually to another DC device used as the decoder circuit). The encoder will transmit the serial data each time the Start/Data input is activated.

This encoded Data word is transmitted in 2 parts. The first part is the preamble information which is a series of 12 "1"s and then a space indicating that the encoded Data is to follow. This preamble information is intended to be used to synchronize a phase locked loop at the receiver or used as a setting time for receivers that have automatic gain control. The second part contains the 7 bits of address and 8 bits of data.

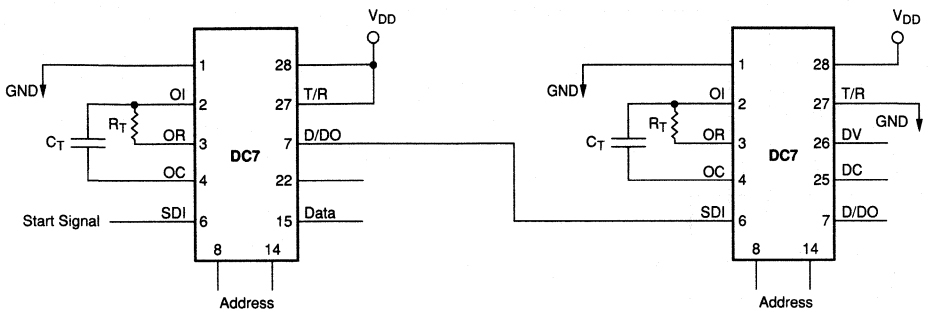
Receive Function

The receive mode is selected by connecting the Transmit/Receive control input to ground. In this mode the circuit will work as a decoder receiving the serial data in Manchester Encoded format and recovering the clock. The incoming data is converted to a 15-bit serial word. It is compared with the local address word by sampling the Address Inputs (7-bits). These bits are usually programmed to the expected Address that will be decoded. If the two Address words match, the decoded output will go to a logic "1" state, but if the two do not match the decoded output will stay low. Also, if the words do not match but the bit stream was valid (i.e., 15-bits of proper timing) then only the output valid signal will go high. If at any time the bit sequence has the wrong timing, the local oscillator and internal comparison circuits will be reset and any new input pulses will be recognized as a new bit stream. Therefore, as with the receiver processing of the preamble information, the 12-bits will be recognized. But, during the 13th interval where no bit transition occurs, the circuit times out and awaits the start bit of the address and data sequence.

The DC7 will only compare the first 7 bits and ignore the state of the last 8- bits — that is, 128 distinct address codes with 8 bits that may be used for data transmission.

Transmit and Receive Address and Data Patterns

DC7 to DC7



Transmitted Bit Sequence

1	X	X	X	X	X	X	X	X	X	X	X	X	X	X	X
	A0						A6	D0							D7

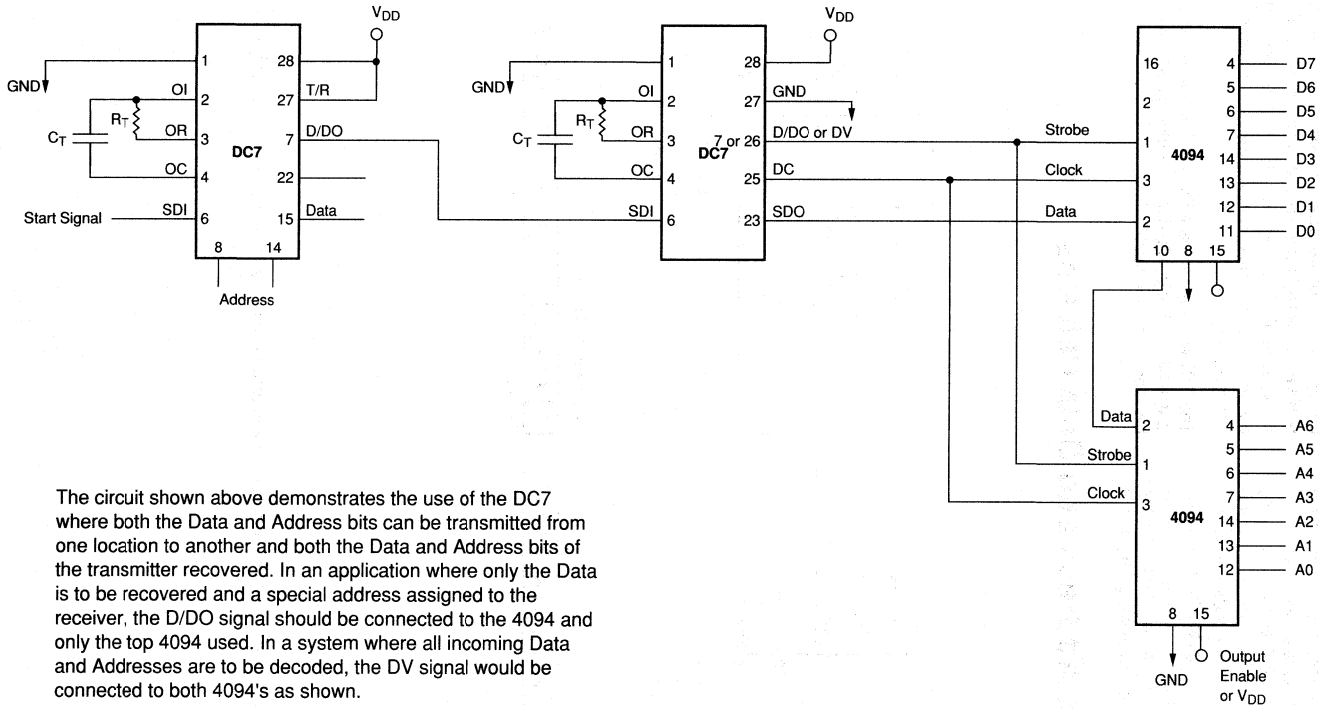
Received Address Code

1	X	X	X	X	X	X	X	D	D	D	D	D	D	D	D
	A0						A6	D0							D7

Note: Bit Sequence Code Format
X = Programmable
0 = Hardwired Internally Zero
1 = Hardwired Internally One
D = Don't Care in Receive Mode (Data)

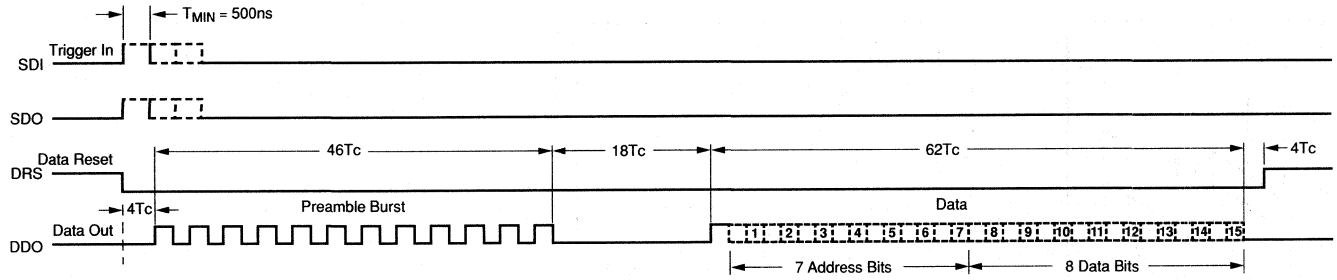
When unused, the DV, DC, DRS and SDO pins should be left floating and **must not** be tied to either a power supply or to ground.

Typical Application



The circuit shown above demonstrates the use of the DC7 where both the Data and Address bits can be transmitted from one location to another and both the Data and Address bits of the transmitter recovered. In an application where only the Data is to be recovered and a special address assigned to the receiver, the D/DO signal should be connected to the 4094 and only the top 4094 used. In a system where all incoming Data and Addresses are to be decoded, the DV signal would be connected to both 4094's as shown.

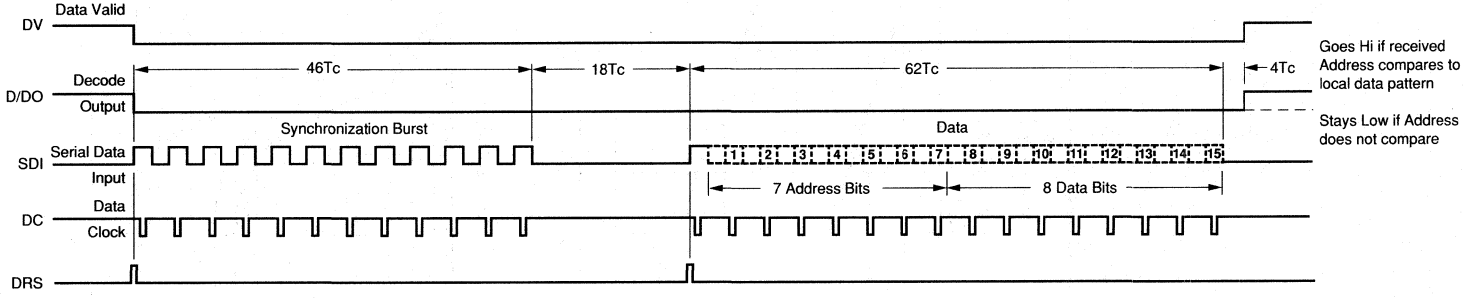
Timing Diagram – Transmit Mode



Total Time Required for Transmission of One Sequence = (DRS – 4Tc) =130Tc

$$Tc = \frac{1}{\text{Clock Frequency}}$$

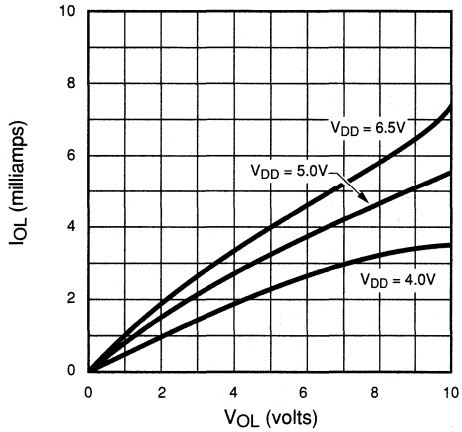
Timing Diagram – Receive Mode



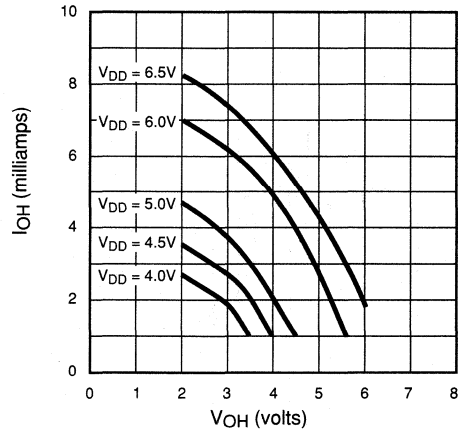
$$Tc = \frac{1}{\text{Clock Frequency}}$$

Typical Performance Curves (T_A = 25°C unless otherwise noted)

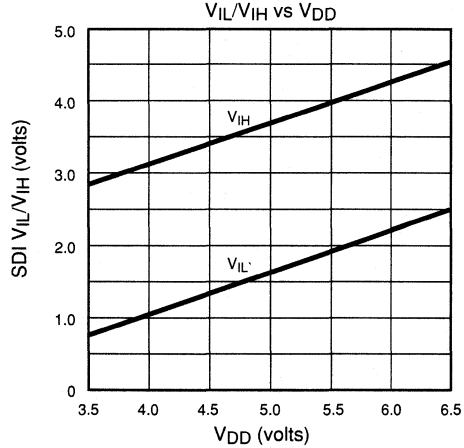
I_{OL} vs V_{DD} vs D_{OL}



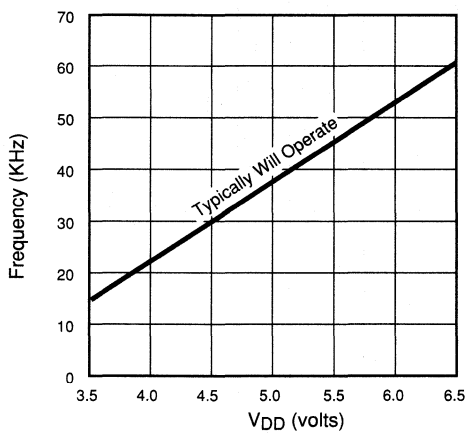
I_{OH} vs V_{DD} vs V_{OH}



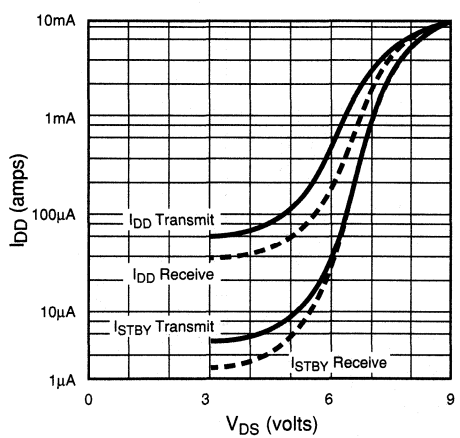
SDI Input
V_{IL}/V_{IH} vs V_{DD}



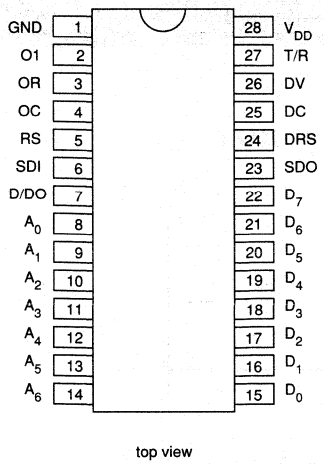
Operating Frequency vs V_{DD}



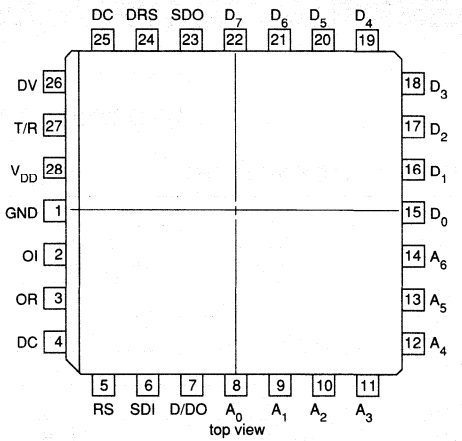
I_{DD} vs V_{DD}



Pin Configuration



28-pin DIP and 28-pin SOW



28-pin J-lead Package

12

Progammable Encoder/Decoder

Ordering Information

Device	Package			
	Plastic DIP (#Pins)	J-Lead PLCC (#Pins)	Plastic SOW Gullwing (#Pins)	Die
ED5	ED5P (18)	—	—	—
ED9	ED9P (18)	—	ED9WG (20)	—
ED10	—	—	ED10WG (20)	—
ED11	ED11P (28)	—	ED11WG (28)	—
ED15	ED15P (28)	ED15PJ (28)	ED15WG (28)	ED15X

Features

- ☐ Manchester Phase Encoding
- ☐ Encoder/Decoder in one circuit
- ☐ Schmitt Trigger Input for excellent noise rejection
- ☐ Built-in Oscillator using non-critical RC Components
- ☐ Zener Diode to regulate the power supply
- ☐ Low Power, High Noise Immunity CMOS technology
- ☐ Ability to Decode Original Signals
- ☐ Automatic Preamble Generation

Applications

- ☐ Smoke & Fire Alarm Control Systems
- ☐ Security Systems
- ☐ Theft Alarm Systems
- ☐ Digital Locks
- ☐ Digital Paging Systems
- ☐ Garage Door Openers
- ☐ Systems that require a Special Identification Code
- ☐ Pocket Pagers
- ☐ Recognition or Transmission

General Description

The ED series is a single monolithic chip using metal-gate CMOS technology for low cost, low power, high yield and high reliability. It is a dual purpose circuit, capable of working either as an encoder, or as decoder of its own transmissions, in applications where exclusive recognition of a special code is required. It will decode up to1 of 32,768 codes. In the transmit mode, each circuit is capable of generating the possible codes by connecting the Data Inputs to V_{DD} or GND for a "1" or a "0". In the receive mode, each circuit is capable of decoding the transmitted signal and simultaneously making a comparison to the local address code for identification.

Absolute Maximum Ratings

Supply Voltage with respect to GND	6.4V
Operating Temperature	-40°C to +85°C
Storage Temperature	-55°C to +150°C
Zener Current	100mA

Note: All inputs except OI contain protection circuitry to prevent damage due to static charges. Care should be exercised to prevent application of voltages outside of the specification range. The OI has a special input protection circuit and special care should be taken with this input.

The above applies to parts with datecodes June, 1991 or earlier. Contact Supertex for the exact date.

Electrical Characteristics

DC Characteristics (V_{DD} = 5.0 ± 5%; GND = 0V; T_A = 25°C)

Symbol	Parameter	Min	Typ Note 1	Max	Unit	Conditions
V_{IH}	Input High Voltage	V_{DD} - 0.3		V_{DD} + 0.3	V	"1" INPUT
V_{IL}	Input Low Voltage	GND- 0.3		0.3	V	"0" INPUT
I_{LKC}	Input Leakage Current		0.1	2.0	µA	V_{IN} = 5.0V for pins T/R, SDI
I_{LC}	Input Load Current	2.0	6.0	20.0	µA	V_{IN} = 5.0V for pins RS, D1-D15
V_{OH}	Output High Voltage	V_{DD} - 0.3			V	V_{DD} = 4.75V, I_{LOAD} = -100µA
V_{OL}	Output Low Voltage			0.3	V	V_{DD} = 4.75V, I_{LOAD} = 100µA
I_{OH}	Output High Current (Sourcing)	-1.0	-1.5		mA	V_{OH} = V_{DD} - 1.0V
I_{OL}	Output Low Current (Sinking)	1.0	3.0		mA	V_{OL} = 1.0V
V_Z	Zener Voltage	5.5	6.4	7.0	V	I_Z = 10µA (Note 2)
		6.0	6.7	7.5	V	I_Z = 10mA (Note 2)
C_{IN}	Input Capacitance			10	pF	(Note 2)
C_{OUT}	Output Capacitance			10	pF	(Note 2)
I_{DD}	Drain Current			10	µA	V_{DD} = 5.0V, all inputs = GND all outputs floating

Notes:
1. Typical values are those values measured in a production sample at V_{CC} = 5.0V.
2 This parameter is periodcally sampled and is not 100% tested.

AC Characteristics (V_{DD} = 5.0 ± 5%; T_A = 25°C)

Symbol	Parameter	Min	Typ Note1	Max	Unit	Conditions
f_c	Clock Frequency	0		20	kHz	R= 150k, C= 100pF; Clock Period (t_c)=1/f_C
t_{SDI}	Start Pulse Width	500			ns	
t_{DDO}	DDO Delay from SDI		5		µs	
t_{DC}	Data Clock Pulse Width		.5t_C		sec	
t_{WORD}	Full Cycle Word Length		130t_C		sec	
R_R	Receiver Oscillator Resistor Tolerance from Transmitter Oscillator Resistor		±10		%	
C_R	Receiver Oscillator Capacitor Tolerance from Transmitter Oscillator Capacitor		±10		%	

Note 1: Typical values are those values measured on a production sample at V_{CC} = 5.0V.

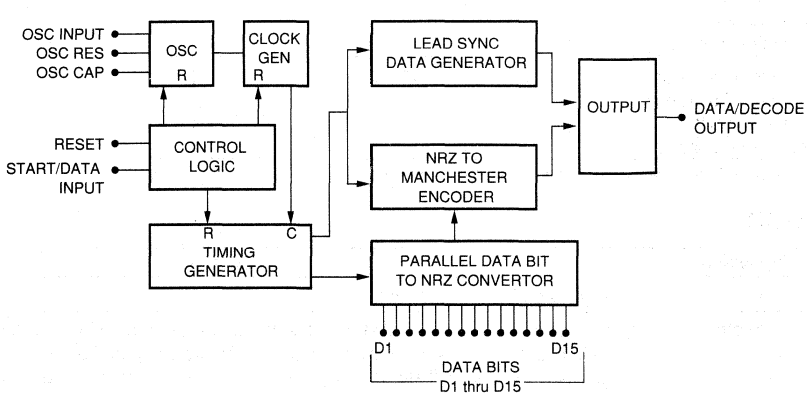
Pin Definition

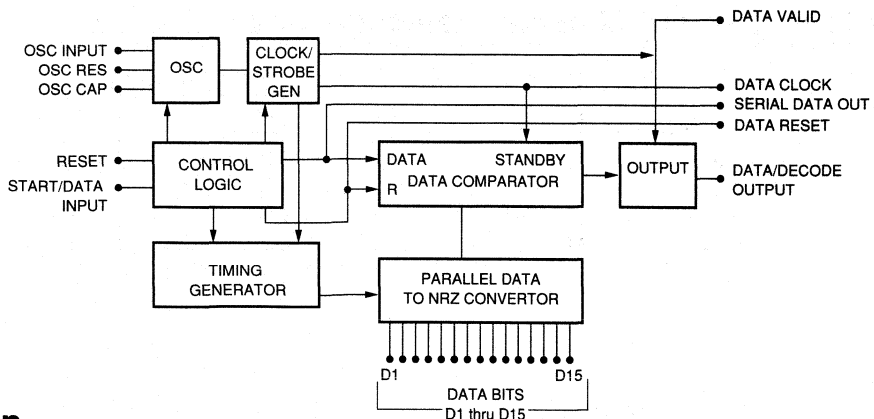
Label	Pin Name	Function
GND	Ground	Supply Potential negative side.
OI	Oscillator Input	This input is to drive the oscillator and is the tie point of the timing resistor (R_T), and the timing capacitor (C_T). It also is connected through a diode to an open drain P-channel device that turns on to V_{DD} when the oscillator is being reset. This input can exceed the power supplies and does during normal oscillator operation.
OR	Oscillator Resistor	Provides phase feedback to the RC timing circuit through the connected timing resistor. Note: This pin is driven high during oscillator reset.
OC	Oscillator Capacitor	Capacitor connection of RC timing circuit provides phased feedback from the oscillator. This pin is driven low during oscillator reset.

RS	Reset Input	This input pin may be used to override the data transmission cycle or to inhibit an SDI input. It clears the D/DO to a low state and resets the internal oscillator and data comparison circuits. This pin may be left open (No Connection) when not used, or driven as an input, or an external capacitor (100pf) to V_{DD} may be added for power-up reset. The Reset function is activated when this input is connected to V_{DD}.
S/DI	Start/Data Input	Start/Data input is a dual function pin. It is used to start the oscillator which enables the transmission of the encoded word in the transmit mode. And in the receive mode, this input receives the serial coded information for processing and comparison.
D/DO	Data/Decode Output	Another dual purpose pin, this pin is the encoded sequence data output in the transmit mode and becomes the decode true output in the receive mode. It indicates that the incoming code has matched the local bit data input address.
D1-D15	Data Bit Inputs	These Inputs provide parallel input data to be sequentially transmitted. The 18-pin package options have some pins omitted and hence these data positions will have logical zeros transmitted. In the receive mode, these imputs become the parallel local address code for comparison with the incoming data. Note that with the ED-11 and ED-5 options, the data bits 11-15 are not used in the comparison when in the receive mode.
SDO	Serial Data Output	This output signal is a buffered S/DI signal after going through the input Schmitt Trigger, a delay circuit, and is the same polarity as the input and can be used to chain a number of receivers together. This output can be connected to the input of a 16-bit shift register (clocked by the DC pin) in a receiver system where data is to be recovered regardless of its comparison to a preset address word.
DRS	Data Reset Output	Data Reset can be used in the receive mode to reset an external data shift register since this Output signal pulse indicates that a new word has just begun processing.
DC	Data Clock Output	The Data Clock output may be used in a receive system since it is the recovered data sync pulses. Also, this output can be used to clock an external shift register where data is to be recovered.
DV	Data Valid Output	This output is triggered low at the start of any input and will remain low until a complete word has been processed. Note that this output simply signals that a valid word has been received and not that the code received has matched the local address code.
T/R	Transmit/ Receive	This is a control input to determine the operating mode. A logic high applied to this input puts it in the transmit mode; a logic low puts it in the receive mode.
V_{DD}	V_{DD}	Positive Supply Potential: This circuit contains an on-chip zener of approximately 6.7 volts across the supply terminals.

Block Diagrams

TRANSMITTER





Operation

ED15 General Description

The ED15 series mode of operation is controlled by the Transmit/Receive control input (T/R). When switched from V_{DD} to GND, the circuit will automatically change the oscillator, Start/Data input, and Data/Decoder Output from Transmit to Receive mode.

The circuit contains an on-chip zener diode to clamp the power supply to around 6.7 volts. The circuit will operate from 4.0 volts to the zener voltage, but operation is recommended at 5 volts ± 5% in order to stabilize the time constants of the oscillator circuit. In order to use the on-chip zener diode, a current limiting resistor of 1K ohm or greater is required. If pull up resistors are used for the D_1 - D_{15} drives, the resistors should be tied to a voltage no higher than that on Pin 28 or 6 volts, whichever is lower.

Output drivers are capable of sinking or sourcing 1.0 mA minimum at 1.0 volt V_{DS}. All inputs are gate protected to both power supplies by internal diodes. The Data Inputs each have pull down resistors to ground so that only a "1" will have to be programmed. This allows the inputs to be programmed by using SPST switches or jumpers to V_{DD} only. The Transmit/Receive input does not have a pull up or pull down resistor. The Start/Data Input also does not have a pull up or pull down resistor, but is applied to a Schmitt Trigger Input circuit to improve noise rejection.

Encoder Function

This function is selected by connecting the Transmit/Receive control input to V_{DD}. This enables the Transmit mode and the circuit to function as an encoder, sampling the 15 Data Input pins' digital information and encoding this parallel data in NRZ format, combining it with the clock in Manchester Code (Phase Encoded), and presenting it to the D/DO pin for transmission (usually to another ED device used as the decoder circuit). The encoder will transmit the serial data each time the Start/Data input is activated.

This encoded Data word is transmitted in 2 parts. The first part is the preamble information which is a series of 12 "1"s, then a space indicating that the encoded Data is to follow. This preamble information is intended to be used to synchronize a phase locked loop at the receiver or used as a setting time for receivers that have automatic gain control. The second part contains the 15 bits of addresses and/or controls.

Decoder Function

The receive mode is selected by connecting the Transmit/Receive control input to ground. In this mode the circuit will work as a decoder, receiving the serial data in Manchester Encoded format and recovering the clock. The incoming data is converted to a 15-bit serial word. It is compared with the local data word by sampling the Data Inputs (15-bits). These bits are usually programmed to the expected Data that will be decoded. If the two data words match, the decoded output will become logic "1" state, but if the two words do not match the decoded output will stay low. Also, if the words do not match but the bit stream was valid (i.e., 15-bits of proper timing) then only the output valid signal will go high. If at any time the bit sequence has the wrong timing, the local oscillator and internal comparison circuits will be reset and any new input pulses will be recognized as a new bit stream. Therefore, as with the receiver processing of the preamble information, the 12 bits will be recognized. But during the 13th interval where no bit transition occurs, the circuit times out and awaits the start bit of the data sequence.

ED5 Option

The 18-pin packaging option of the ED11 die is called ED5. In the transmit mode it is only capable of 5 bits of programmable code. All the other bits are held at zero. But in the receive mode, the circuit has the five (32) unlock code bits plus the last four transparent bits of the ED11. The ED5 also supplies the necessary output signals to process the 4 bits of control data.

ED9 Option

The ED9 is an 18-pin packaging of the ED15 die. The operation and function of this circuit is the same as the ED15; the only difference being the available pins. In the transmit mode the circuit is only capable of encoding 9 bits of data, the other 6 bits are not programmable and remain zeros. The pin configuration also drops DV, DC, DRS, and SDO such that the circuit can now only respond to a data match condition on the only output, #D/DO. In the receive mode the circuit can decode the same 9 bits of data, enabling up to 512 possible addresses.

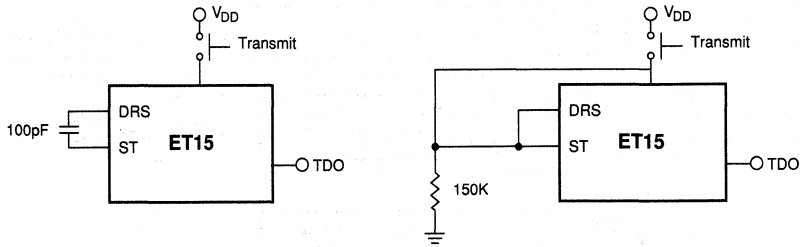
ED10 Option

TheED10 is an ED9 in the 20-pin package. The 2 additional pins are one more data pin (hence ED10) and the DRS pin. The latter is useful for multiple transmissions as shown in the Figures below. This can lead to more reliable reception in some circumstances.

ED11 Option

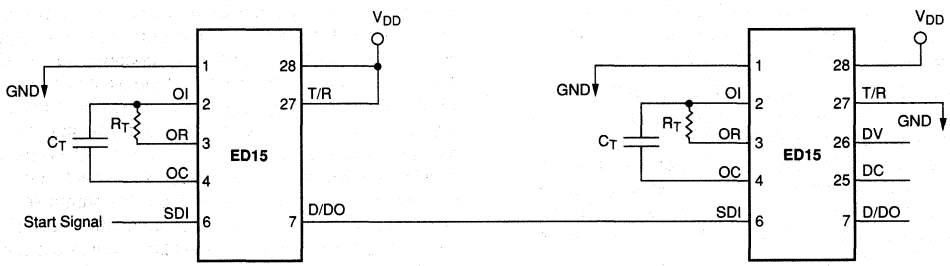
The ED11 differs from the ED15 in that in the receive mode the ED11 will only compare the first 11 bits and ignore the state of the last 4 bits; that is, 2048 distinct address codes with 4 bits may be used for control data transmission.

Two Ways to Implement Multiple Transmissions (all except ED9)



Transmit and Receive Data Patterns of ED-Series Devices

ED15 to ED15



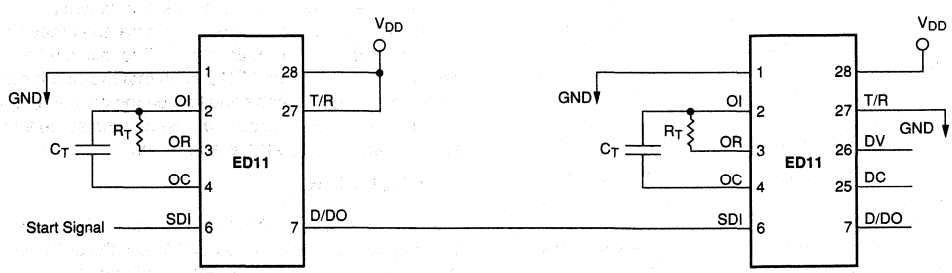
Transmitted Bit Sequence

1	X	X	X	X	X	X	X	X	X	X	X	X	X	X	X
D1															D15

Received Address Code

1	X	X	X	X	X	X	X	X	X	X	X	X	X	X	X
D1															D15

ED11 to ED11



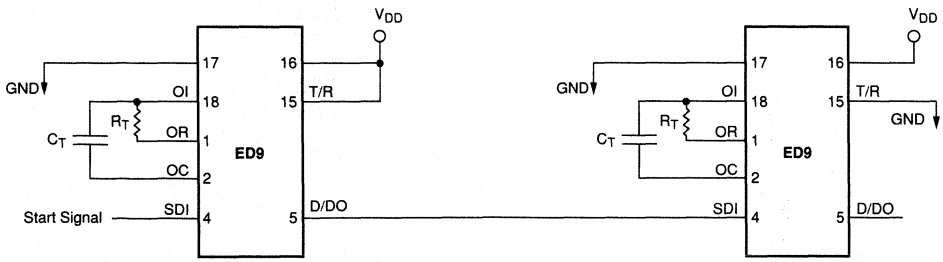
Transmitted Bit Sequence

1	X	X	X	X	X	X	X	X	X	X	X	X	X	X	X
D1															D15

Received Address Code

1	X	X	X	X	X	X	X	X	X	X	X	X	X	X	X
D1															D15

ED9 to ED9



Transmitted Bit Sequence

1	0	0	0	X	X	X	X	0	X	0	0	X	X	X	X

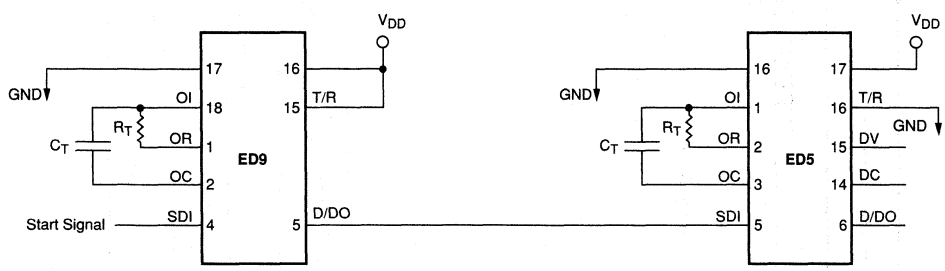
D1 D15

Received Address Code

1	0	0	0	X	X	X	X	0	X	0	0	X	X	X	X

D1 D15

ED9 to ED5



Transmitted Bit Sequence

1	0	0	0	X	X	X	X	0	X	0	0	X	X	X	X

D1 D15

Received Address Code

1	0	0	0	X	X	X	X	0	X	0	0	D	D	D	D

D1 D15

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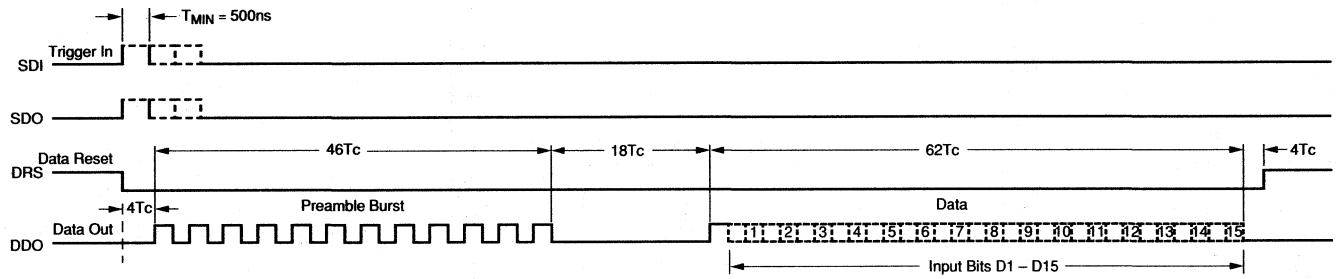
Notes:

Bit Sequence Code Format
- X = Programmable
- 0 = Hardwired Internally Zero
- 1 = Hardwired Internally One
- D = Don't Care in Receive Mode

When unused, the DV, DC, DRS and SDO pins should be left floating and **must not** be tied to either a power supply or to ground.

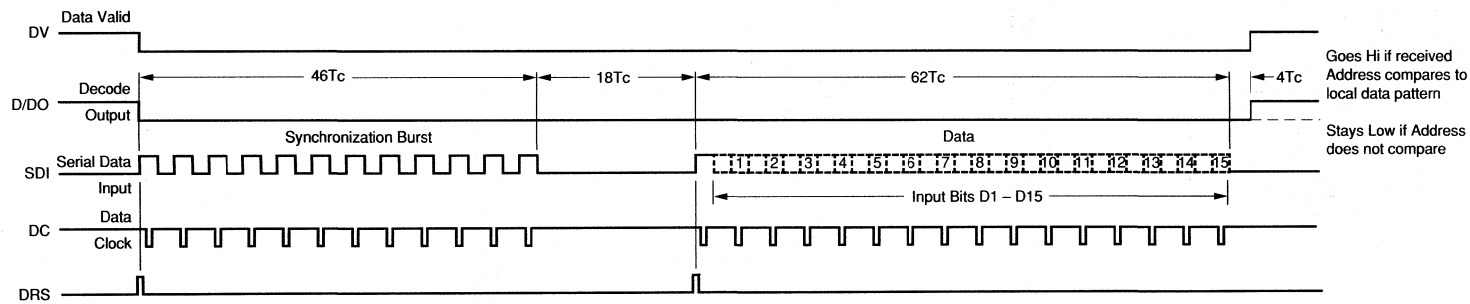
Timing Diagram – Transmit Mode



Total Time Required for Transmission of One Sequence = (DRS – 4Tc) =130Tc

$$Tc = \frac{1}{\text{Clock Frequency}}$$

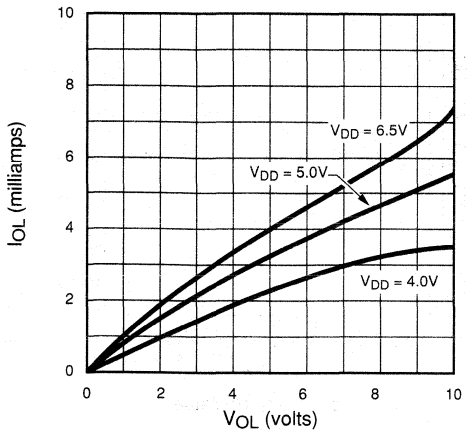
Timing Diagram – Receive Mode



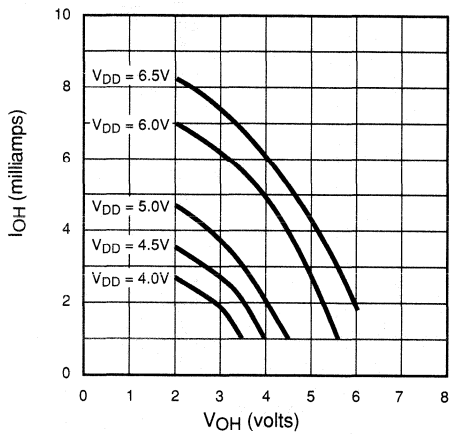
$$Tc = \frac{1}{\text{Clock Frequency}}$$

Typical Performance Curves (T_A = 25°C unless otherwise noted)

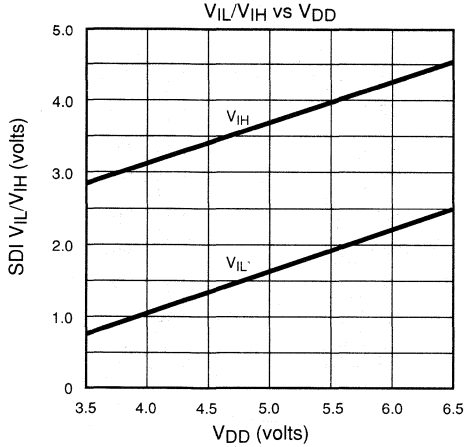
I_{OL} vs V_{DD} vs D_{OL}



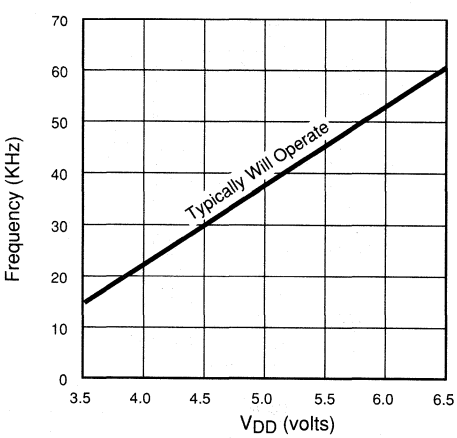
I_{OH} vs V_{DD} vs V_{OH}



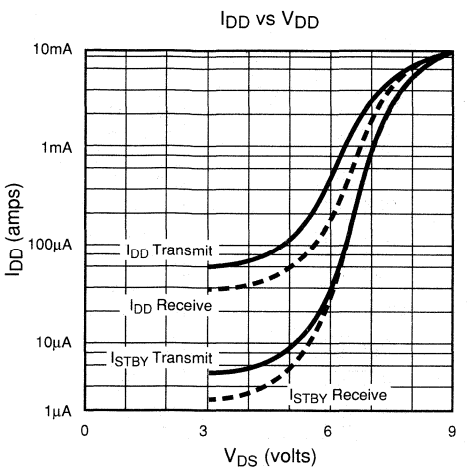
SDI Input
V_{IL}/V_{IH} vs V_{DD}



Operating Frequency vs V_{DD}



I_{DD} vs V_{DD}



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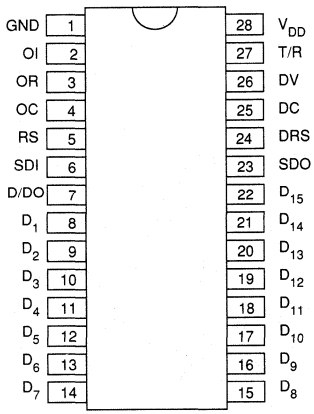
Pin Configuration

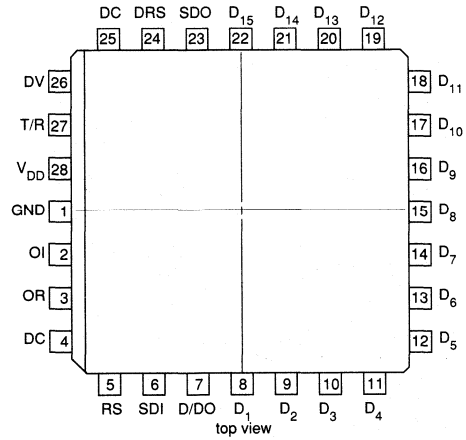
ED15 & ED11



top view

28-pin DIP

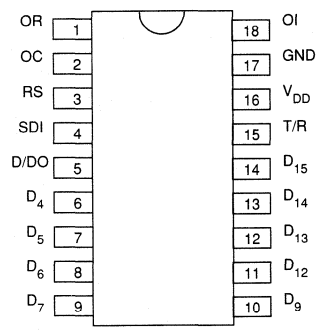
ED15



top view

28-pin J-lead Package

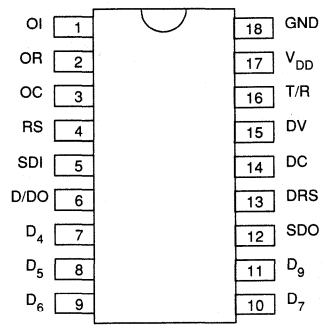
ED9



top view

18-pin DIP

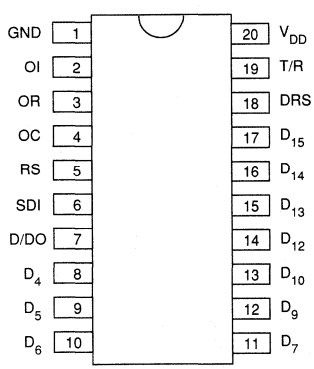
ED5



top view

18-pin DIP

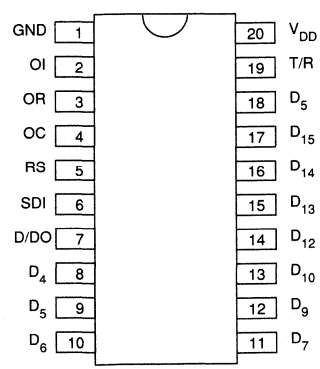
ED9



top view

20-pin DIP/SOW 20

ED10



top view

20-pin DIP/SOW 20

Programmable Encoder

Ordering Information

Device	Package	Order No.
ET13	20-Pin Plastic DIP	ET13P
ET13	20-Pin SO Surface Mount	ET13WG

Features

- ☐ High Density Transmit only ED Device
- ☐ 13 Address Bits (8192 Addresses)
- ☐ Manchester Phase Encoding
- ☐ Transmitter Compatible with ED15 Series
- ☐ Schmitt Trigger Input for excellent noise reduction
- ☐ Built-in Oscillator using non-critical RC components
- ☐ Zener Diode to regulate the power supply
- ☐ Low power, High Noise Immunity
- ☐ 20-Pin Surface Mount SO package
- ☐ Automatic Preamble Generation

Applications

- ☐ Smoke and Fire Alarm Systems
- ☐ Pocket Pagers
- ☐ Digital Locks
- ☐ Theft Alarm Systems
- ☐ Security Systems
- ☐ Digital Paging Systems
- ☐ Special Identification Code Systems
- ☐ Remote Sensor Data Acquisition Systems
- ☐ Single Channel Digital Transmission of Information

Absolute Maximum Ratings

Supply Voltage with respect to V_{SS}	6.4V
Operating Temperature	-40°C to +85°C
Storage Temperature	-55°C to +150°
Zener Current	100mA

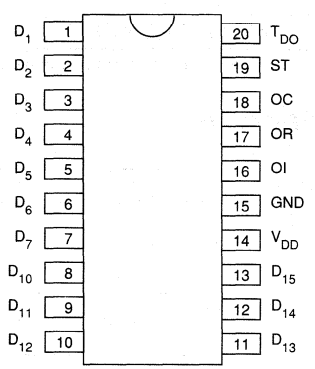
Note: All inputs except OI contain protection circuitry to prevent damage due to static charges. Care should be exercised to prevent application of voltages outside of the specification range. The OI has a special input protection circuit and special care should be taken with this input.
The above applies to parts with datecodes June, 1991 or earlier. Contact Supertex for the exact date.

General Information

The ET13 is a single monolithic chip using metal gate CMOS technology for low cost, low power, high yield and high reliability. This circuit is capable of working as an encoder in applications where exclusive recognition of address codes is required. This circuit is capable of generating 8192 codes by connecting the Address Inputs to V_{DD} for a "1", or allowed to Float for a "0".

The ET13 Transmitter is a device in the Supertex ED Series of parts that is communication compatible with any other ED Series device. The ET13 provides the maximum number of address codes in a small package which makes it ideally suited for remote security transmitter applications where receiver operation is unnecessary. The ET13 is also available in a new 20-pin surface mount SOW package with .050-inch pitch Gullwing leads, providing high package density for remote transmitter applications.

Pin Configuration



top view

20-pin DIP/SOW 20

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Electrical Characteristics

DC Characteristics (V_{DD} = 5.0 ± 5%; GND = 0.0V; T_A = 25°C)

Symbol	Parameter	Min	Typ (Note 1)	Max	Unit	Conditions
V_{IH}	Input High Voltage	V_{DD} - 0.3		V_{DD} + 0.3	V	"1" INPUT
V_{IL}	Input Low Voltage	GND- 0.3		0.3	V	"0" INPUT
I_{LKC}	Input Leakage Current		0.1	2.0	µA	V_{IN} = 5.0V for ST
I_{LC}	Input Load Current	2.0	6.0	20.0	µA	V_{IN} = 5.0V for pins RS, D1-D15
V_{OH}	Output High Voltage	V_{DD} - 0.3			V	V_{DD} = 4.75V, I_{LOAD} = -100µA
V_{OL}	Output Low Voltage			0.3	V	V_{DD} = 4.75V, I_{LOAD} = 100µA
I_{OH}	Output High Current (Sourcing)	-1.0	-1.5		mA	V_{OH} = V_{DD} -1.0V
I_{OL}	Output Low Current (Sinking)	1.0	3.0		mA	V_{OL} = 1.0V
V_Z	Zener Voltage	5.5	6.4	7.0	V	I_Z = 10µA (Note 2)
		6.0	6.7	7.5	V	I_Z = 10mA (Note 2)
C_{IN}	Input Capacitance			10	pF	(Note 2)
C_{OUT}	Output Capacitance			10	pF	(Note 2)
I_{DD}	Drain Current			10	µA	V_{DD} = 5.0V, all inputs = GND all inputs floating

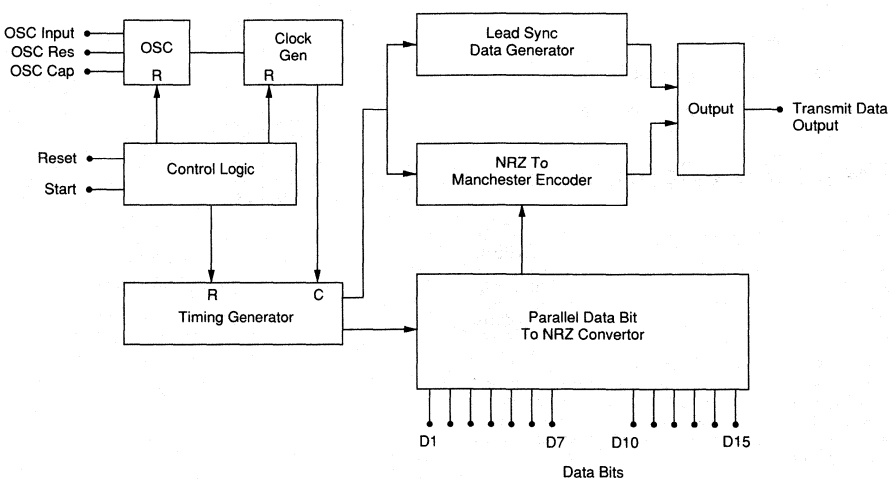
Notes :
1. Typical values are those values measured in a production sample at V_{CC} = 5.0V.
2. This parameter is periodcally sampled and is not 100% tested.

AC Characteristics (V_{DD} = 5.0 ± 5%; T_A = 25°C)

Symbol	Parameter	Min	Typ (Note 1)	Max	Unit	Conditions
f_c	Clock Frequency	0		20	kHz	R = 150k, C = 100pF; Clock Period (t_c) = 1/f_c
t_{st}	Start Pulse Width	500			ns	
T_{DO}	TDO Delay from SDI		5		µs	
t_{WORD}	Full Cycle Word Length		130t_c		sec	

Note 1: Typical values are those values measured on a production sample at V_{CC} = 5.0V.

Block Diagram



Pin Definition

Label	Pin Name	Function
GND	Ground	Supply Potential negative side.
OI	Oscillator Input	This input is to drive the oscillator and is the tie point of the timing resistor (RT), and the timing capacitor (CT). It also is connected through a diode to an open drain P-channel device that turns on to V_{DD} when the oscillator is being reset. This input can exceed the power supplies and does during normal oscillator operation.
OR	Oscillator Resistor	Provides phase feedback to the RC timing circuit through the connected timing resistor. NOTE: This pin is driven high during oscillator reset.
OC	Oscillator Capacitor	Capacitor connection of RC timing circuit provides phased feedback from the oscillator. This pin is driven low during oscillator reset.
RS	Reset Input	This input pin may be used to override the data transmission cycle or to inhibit an SDI input. It clears the D/DO to a low state and resets the internal oscillator and data comparison circuits. This pin may be left open (No Connection) when not used, or it may be driven as an input, or an external capacitor (100pF) to V_{DD} may be added for power-up reset. The Reset function is activated when this input is connected to V_{DD}.
ST	Start	Start input is used to start the oscillator which enables the transmission of encoded word.
TDO	Transmit Data Output	This pin is the encoded sequence data output.
D1-D15	Data Bit Inputs	In the ED series devices, these inputs provide parallel input data to be sequentially transmitted. The 20-pin ET13 has some pins omitted and, hence, these data positions will have logical zeros transmitted.
V_{DD}	V_{DD}	Positive Supply Potential: This circuit contains an on-chip zener of approximately 6.7 volts across the supply terminals.

Operation

General

The ET13 is a programmable transmitter, encoding 13 data bits into a serial Manchester code bit stream.

The ET13 contains an on-chip zener diode to clamp the power supply to around 6.7 volts. The circuit will operate from 4.0 volts to the zener voltage, but operation is recommended at 5 volts ±5%, or from a regulated power supply in order to stabilize the time constants of the oscillator circuit. In order to use the on-chip zener diode, a current limiting resistor of 1K ohm or greater is required. If pull-up resistors are used for the Data Inputs, the resistors should be tied to a voltage no higher than that on Pin 14 or 6 volts, whichever is lower.

Output drivers are capable of sinking or sourcing 1.0 mA minimum at 1.0 volts V_{DS}. All inputs are gate protected to both power supplies by internal diodes. The Address Data Inputs of the ET13 each have pull down resistors to ground so that only a "1" will have to be programmed. This allows the inputs to be programmed by using SPST switches or jumpers to V_{DD} only. The Start/Data Input also does not have a pull up or pull down resistor, but is applied to a Schmitt Trigger input circuit to improve noise rejection.

Function

The ET13 functions as an encoder, sampling the 13 Data Input pins' digital information and encoding this parallel data in NRZ format, combining it with the clock in Manchester Code (Phase Encoded) and presenting it to the TDO pin for transmission (usually to an ED device used as the decoder circuit). The encoder will transmit the serial data each time the Start (ST) input is activated.

This encoded Data word is transmitted in two parts. The first part is preamble information which is a series of 12 "1's" and then a space indicating that the encoded Data is to follow. This preamble information is intended to be used to synchronize a phase locked-loop at the receiver or used as a setting time for receivers that have automatic gain control. The second part contains the 13 bits of Data.

Transmit and Receive Data Patterns of ED-Series Devices

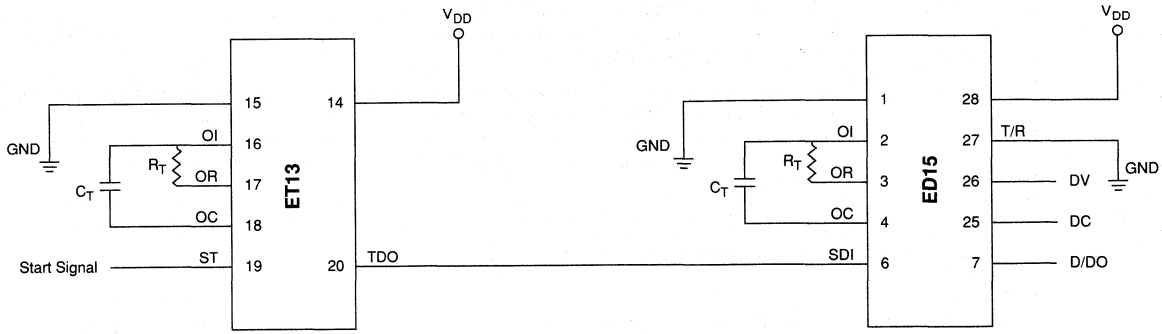
Note: Bit Sequence Code Format

x = Programmable

0 = Hardwired Internally Zero

1 = Hardwired Internally One

ET13 to ED15



Transmitted Bit Sequence

1	X	X	X	X	X	X	X	0	0	X	X	X	X	X	X

D1 D15

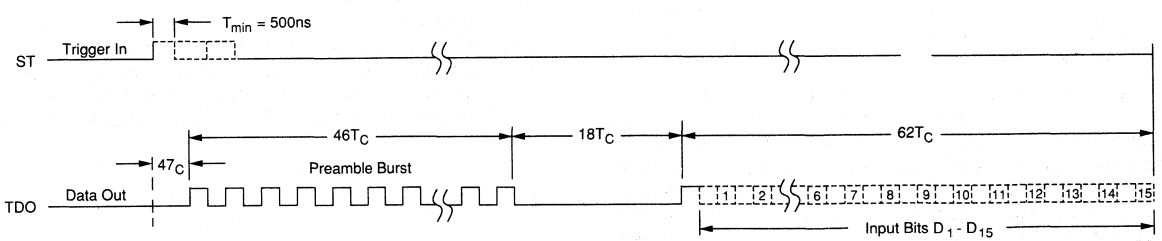
Received Address Code

1	X	X	X	X	X	X	X	0	0	X	X	X	X	X	X

D1 D15

Timing Diagram – Transmit

Timing Diagram – Transmit

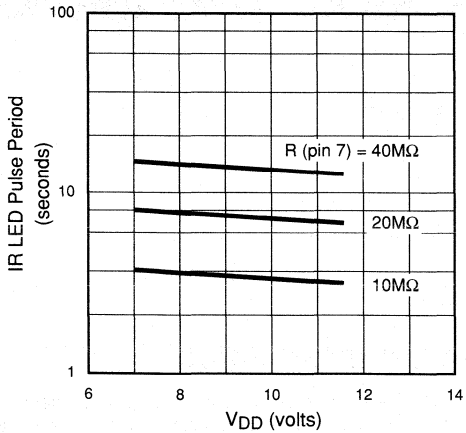


Total Time Required for Transmission of One Sequence = $130T_C$

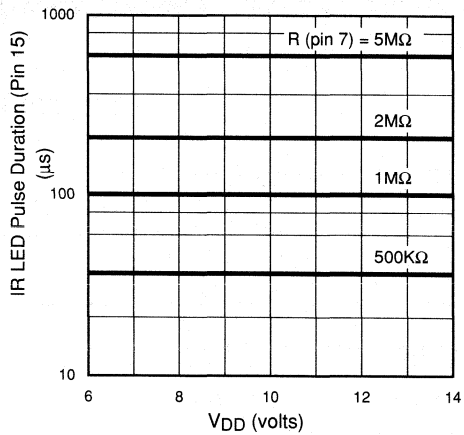
$T_C = \frac{1}{\text{CLOCK FREQUENCY}}$

Typical Performance Curves (T_A = 25°C unless otherwise noted)

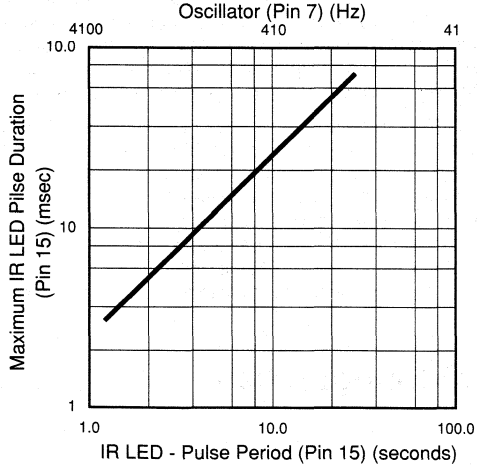
T_{LED} vs V_{DD}



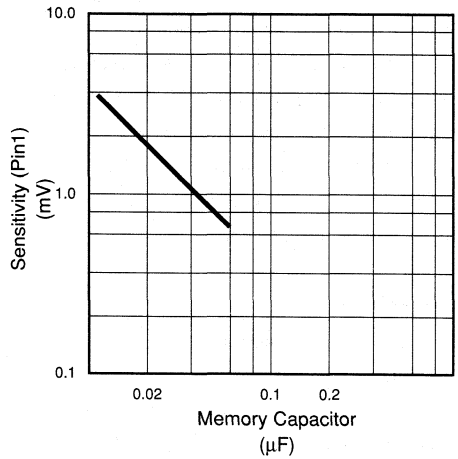
T_{PD} vs V_{DD}



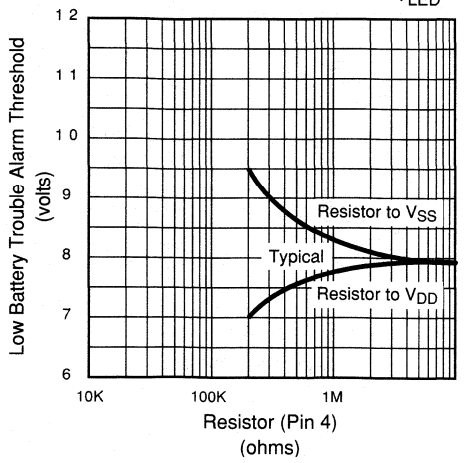
IR LED vs T_{LED} vs Oscillator



Detector Sensitivity vs C_{MEM}



$$I_{AVG}\,(LED) = [(I_{OH}(15)) + I_{LED}]\,\frac{T_{PD}}{T_{LED}}$$



Programmable Encoder

Ordering Information

Device	Package	Order No.
ET15	20-Pin Plastic DIP	ET15P
ET15	20-Pin SO Surface Mount	ET15WG

Features

- ☐ High Density Transmit only ED Device
- ☐ 12 Address Bits (4096 Addresses)
- ☐ Manchester Phase Encoding
- ☐ Data Reset (DRS) Pin for Multiple Transmissions
- ☐ Transmitter Compatible with ED15 Series
- ☐ Schmitt Trigger Input for excellent noise reduction
- ☐ Built-in Oscillator using non-critical RC components
- ☐ Zener Diode to regulate the power supply
- ☐ Low power, High Noise Immunity
- ☐ 20-Pin Surface Mount SO package
- ☐ Automatic Preamble Generation

Applications

- ☐ Smoke and Fire Alarm Systems
- ☐ Pocket Pagers
- ☐ Digital Locks
- ☐ Theft Alarm Systems
- ☐ Security Systems
- ☐ Digital Paging Systems
- ☐ Special Identification Code Systems
- ☐ Remote Sensor Data Acquisition Systems
- ☐ Single-Channel Digital Transmission of Information

Absolute Maximum Ratings

Supply Voltage with respect to V_{SS}	6.4V
Operating Temperature	-40°C to +85°C
Storage Temperature	-55°C to +150°C
Zener Current	100mA

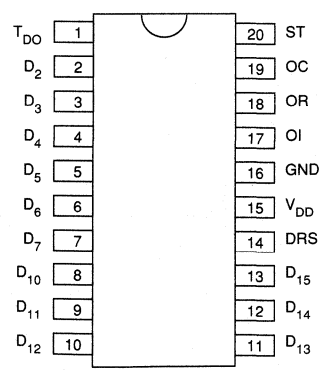
Note: All inputs except OI contain protection circuitry to prevent damage due to static charges. Care should be exercised to prevent application of voltages outside of the specification range. The OI is a special circuit and extra care should be taken with this input.

General Information

The ET15 is a single monolithic chip using metal gate CMOS technology for low cost, low power, high yield and high reliability. This circuit is capable of working as an encoder in applications where exclusive recognition of address codes is required. This circuit is capable of generating 4096 codes by connecting the Address Inputs to V_{DD} for a "1", or allowing them to float for a "0". The ET-15 permits multiple transmissions of data, improving the probability of valid reception in high-noise environments.

The ET15 Transmitter is a device in the Supertex ED Series of parts that is communication-compatible with any other ED Series device. The ET15 provides the maximum number of address codes in a small package which makes it ideally suited for remote security transmitter applications where receiver operation is unnecessary. The ET15 is also available in a new 20-pin surface mount SOW package with .050-inch pitch Gullwing leads, providing high package density for remote transmitter applications.

Pin Configuration



top view

20-pin DIP/SOW 20

Electrical Characteristics

DC Characteristics (V_{DD} = 5.0 ± 5%; GND = 0.0V; T_A = 25°C)

Symbol	Parameter	Min	Typ (Note 1)	Max	Unit	Conditions
V_{IH}	Input High Voltage	V_{DD} - 0.3		V_{DD} + 0.3	V	"1" INPUT
V_{IL}	Input Low Voltage	GND- 0.3		0.3	V	"0" INPUT
I_{LKC}	Input Leakage Current		0.1	2.0	µA	V_{IN} = 5.0V for ST
I_{LC}	Input Load Current	2.0	6.0	20.0	µA	V_{IN} = 5.0V for pins RS, D2-D15
V_{OH}	Output High Voltage	V_{DD} - 0.3			V	V_{DD} = 4.75V, I_{LOAD} = -100µA
V_{OL}	Output Low Voltage			0.3	V	V_{DD} = 4.75V, I_{LOAD} = 100µA
I_{OH}	Output High Current (Sourcing)	-1.0	-1.5		mA	V_{OH} = V_{DD} -1.0V
I_{OL}	Output Low Current (Sinking)	1.0	3.0		mA	V_{OL} = 1.0V
V_Z	Zener Voltage	5.5	6.4	7.0	V	I_Z = 10µA (Note 2)
		6.0	6.7	7.5	V	I_Z = 10mA (Note 2)
C_{IN}	Input Capacitance			10	pF	(Note 2)
C_{OUT}	Output Capacitance			10	pF	(Note 2)
I_{DD}	Drain Current			10	µA	V_{DD} = 5.0V, all inputs = GND all inputs floating

Notes:

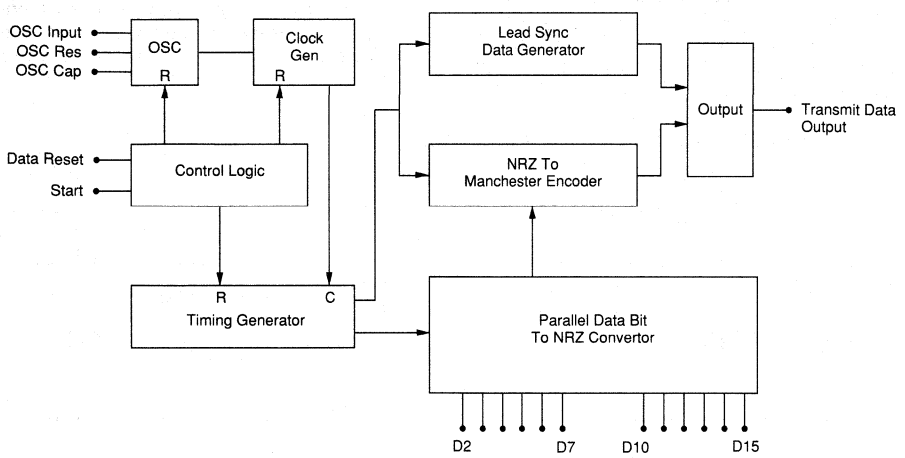
1. Typical values are those values measured in a production sample at V_{CC} = 5.0V.
2.: This parameter is periodically sampled and is not 100% tested.

AC Characteristics (V_{DD} = 5.0 ± 5%; T_A = 25°C)

Symbol	Parameter	Min	Typ (Note 1)	Max	Unit	Conditions
f_C	Clock Frequency	0		15	kHz	R = 150k, C = 100pF; Clock Period (t_C) = 1/f_C
t_{ST}	Start Pulse Width	500			ns	
T_{DO}	TDO Delay from SDI		5		µs	
t_{WORD}	Full Cycle Word Length		130t_C		sec	

Note 1:Typical values are those values measured on a production sample at V_{CC} = 5.0V.

Block Diagram



Pin Definition

Label	Pin Name	Function
GND	Ground	Supply Potential negative side.
OI	Oscillator Input	This input is to drive the oscillator and is the tie point of the timing resistor (RT), and the timing capacitor (CT). It also is connected through a diode to an open drain P-channel device that turns on to V_{DD} when the oscillator is being reset. This input can exceed the power supplies and does so during normal oscillator operation.
OR	Oscillator Resistor	Provides phase feedback to the RC timing circuit through the connected timing resistor. NOTE: This pin is driven high during oscillator reset.
OC	Oscillator Capacitor	Capacitor connection of RC timing circuit provides phased feedback from the oscillator. This pin is driven low during oscillator reset.
DRS	Data Reset	This output goes high after a valid data transmission (see Timing Diagram). This may be used to either indicate a completed transmission or to restart transmission.
ST	Start	Start input is used to start the oscillator which enables the transmission of encoded word.
TDO	Transmit Data Output	This pin is the encoded sequence data output.
D2-D15	Data Bit Inputs	In the ED series devices, these inputs provide parallel input data to be sequentially transmitted. The 20-pin ET15 has some pins omitted and, hence, these data positions will have logical zeros transmitted.
V_{DD}	V_{DD}	Positive Supply Potential: This circuit contains an on-chip zener of approximately 6.7 volts across the supply terminals.

Operation

General

The ET15 is a programmable transmitter, encoding 12 data bits into a serial Manchester code bit stream.

The ET15 contains an on-chip zener diode to clamp the power supply to around 6.7 volts. The circuit will operate from 4.0 volts to the zener voltage, but operation is recommended at 5 volts ±5%, or from a regulated power supply in order to stabilize the time constants of the oscillator circuit. In order to use the on-chip zener diode, a current limiting resistor of 1K ohm or greater is required. If pull-up resistors are used for the Data Inputs, the resistors should be tied to a voltage no higher than that on Pin 14 or 6 volts, whichever is lower.

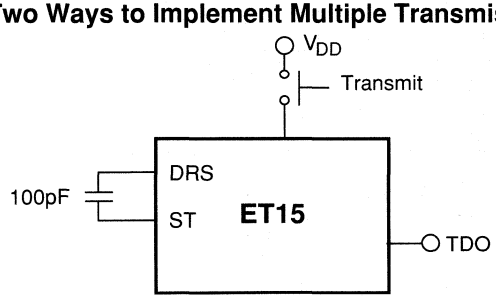
Output drivers are capable of sinking or sourcing 1.0 mA minimum at 1.0 volts V_{DS}. All inputs are gate protected to both power supplies by internal diodes. The Address Data Inputs of the ET15 each have pull-down resistors to ground so that only a "1" will have to be programmed. This allows the inputs to be programmed by using SPST switches or jumpers to V_{DD} only. The Start/Data Input also does not have a pull-up or pull-down resistor, but is applied to a Schmitt Trigger input circuit to improve noise rejection.

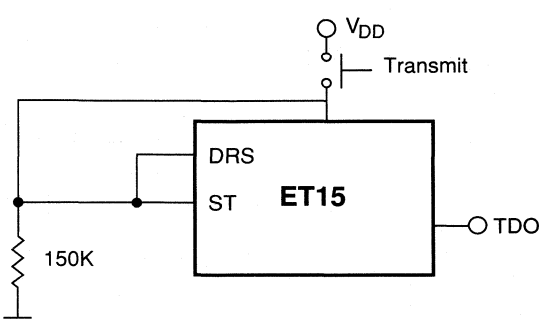
Function

The ET15 functions as an encoder, sampling the 12 Data Input pins' digital information and encoding this parallel data in NRZ format, combining it with the clock in Manchester Code (Phase Encoded) and presenting it to the TDO pin for transmission (usually to an ED device used as the decoder circuit). The encoder will transmit the serial data each time the Start (ST) input is activated. For multiple transmissions of the preamble/encoded data, the DRS pin may be connected to the ST input, with the TRANSMIT function controlled by a push button switch in the V_{DD} line. (See diagrams below.) In high-noise environments, multiple transmissions can improve the probability of a valid received transmission.

This encoded Data word is transmitted in two parts. The first part is preamble information which is a series of 12 "1's" and then a space indicating that the encoded Data is to follow. This preamble information is intended to be used to synchronize a phase-locked loop at the receiver or used as a setting time for receivers that have automatic gain control. The second part contains the 12 bits of Data.

Two Ways to Implement Multiple Transmissions





Transmit and Receive Data Patterns of ED-Series Devices

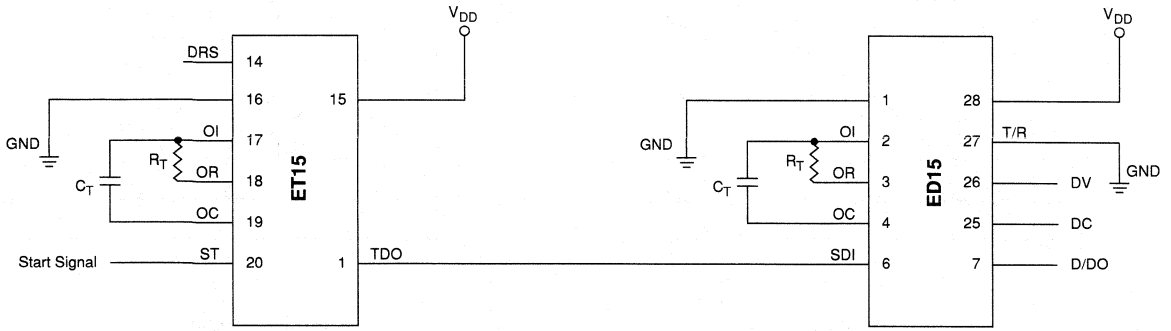
Note: Bit Sequence Code Format

x = Programmable

0 = Hardwired Internally Zero

1 = Hardwired Internally One

ET15 to ED15



Transmitted Bit Sequence

1	0	X	X	X	X	X	X	0	0	X	X	X	X	X	X

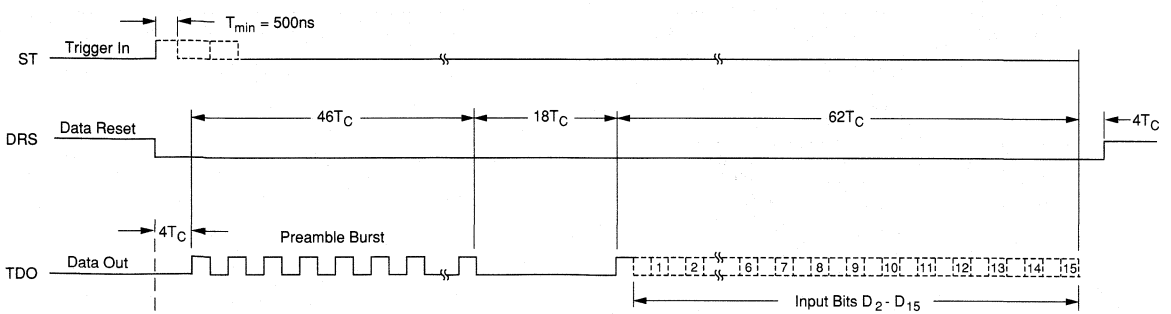
D1 D8 D9 D15

Received Address Code

1	0	X	X	X	X	X	X	0	0	X	X	X	X	X	X

D1 D8 D9 D15

Timing Diagram – Transmit

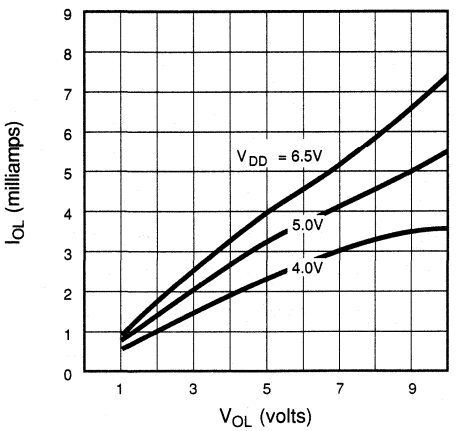


Total Time Required for Transmission of One Sequence = (DRS – $4T_C$) = $130T_C$

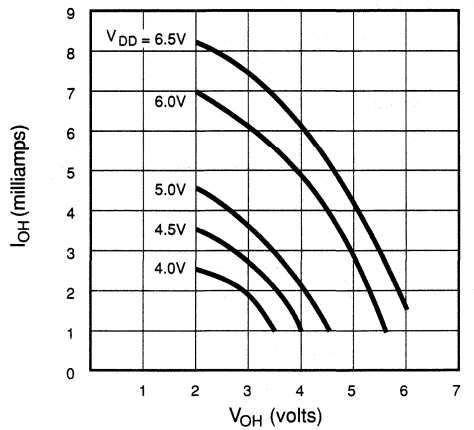
$T_C = \frac{1}{\text{CLOCK FREQUENCY}}$

Typical Performance Curves (T_A = 25°C unless otherwise noted)

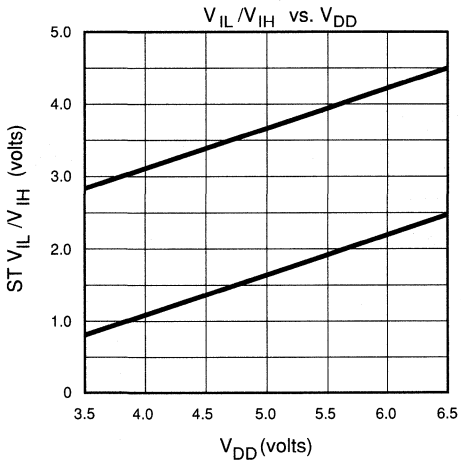
I_{OL} vs. V_{DD} vs. V_{OL}



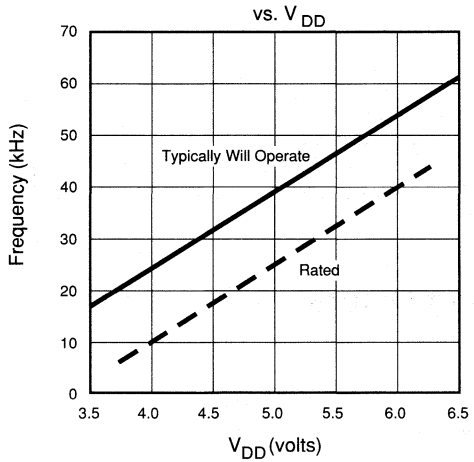
I_{OH} vs. V_{DD} vs. V_{OH}



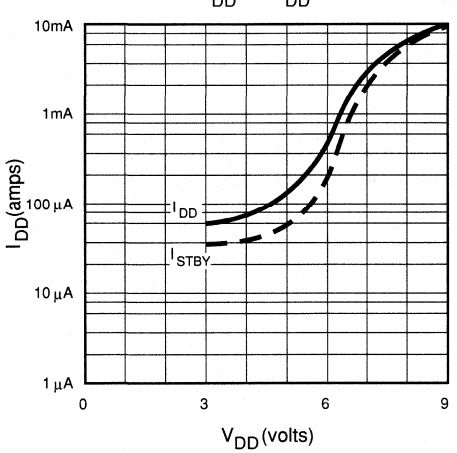
ST Input
V_{IL}/V_{IH} vs. V_{DD}



Operating Frequency
vs. V_{DD}



I_{DD} vs. V_{DD}



Microprocessor Supervisory Circuits

Ordering Information

Device	Temperature Range	Package	Order Number
MP690	0°C to + 70°C	8 Lead Plastic DIP	MP690P
	-40°C to + 85°C	8 Lead Plastic DIP	MP690MP
	-40°C to + 85°C	8 Lead CERDIP	MP690MD
	-55°C to +125°C	8 Lead CERDIP	RCMP690D
MP691	0°C to + 70°C	16 Lead Plastic DIP	MP691P
	0°C to + 70°C	16 Lead Wide SO	MP691WG
	-40°C to + 85°C	16 Lead Plastic DIP	MP691MP
	-40°C to + 85°C	16 Lead CERDIP	MP691MD
	-40°C to + 85°C	16 Lead Wide SO	MP691MWG
	-55°C to +125°C	16 Lead CERDIP	RCMP691D
MP692	0°C to + 70°C	8 Lead Plastic DIP	MP692P
	-40°C to + 85°C	8 Lead Plastic DIP	MP692MP
	-40°C to + 85°C	8 Lead CERDIP	MP692MD
	-55°C to +125°C	8 Lead CERDIP	RCMP692D

Device	Temperature Range	Package	Order Number
MP693	0°C to + 70°C	16 Lead Plastic DIP	MP693P
	0°C to + 70°C	16 Lead Small Outline	MP693WG
	-40°C to + 85°C	16 Lead Plastic DIP	MP693MP
	-40°C to + 85°C	16 Lead CERDIP	MP693MD
	-40°C to + 85°C	16 Lead Small Outline	MP693MWG
	-55°C to +125°C	16 Lead CERDIP	RCMP693D
MP694	0°C to + 70°C	8 Lead Plastic DIP	MP694P
	-40°C to + 85°C	8 Lead Plastic DIP	MP694MP
	-40°C to + 85°C	8 Lead CERDIP	MP694MD
	-55°C to +125°C	8 Lead CERDIP	RCMP694D
MP695	0°C to + 70°C	16 Lead Plastic DIP	MP695P
	0°C to + 70°C	16 Lead Small Outline	MP695WG
	-40°C to + 85°C	16 Lead Plastic DIP	MP695MP
	-40°C to + 85°C	16 Lead CERDIP	MP695MD
	-40°C to + 85°C	16 Lead Small Outline	MP695MWG
	-55°C to +125°C	16 Lead CERDIP	RCMP695D

Features

- ☐ Precision Voltage Monitor:
  4.65V in MP690, MP691, MP694, and MP695
  4.40V in MP692 and MP693
- ☐ Power OK/Reset Time Delay – 50, 200ms, or adjustable
- ☐ Watchdog Timer –100ms, 1.6 sec, or adjustable
- ☐ Minimum Component Count
- ☐ 1μA Standby Current
- ☐ Battery Backup Power Switching
- ☐ Onboard Gating of Chip Enable Signals
- ☐ Voltage Monitor for Power Fail or Low Battery Warning

Applications

- ☐ Computers
- ☐ Controllers
- ☐ Intelligent Instruments
- ☐ Automotive Systems
- ☐ Critical μP Power Monitoring

General Description

The MP690 Family of supervisory circuits reduces the complexity and number of components required for power supply monitoring and battery control functions in microprocessor systems. These include μP reset and backup-battery switchover, watchdog timer, CMOS RAM write protection, and power-failure warning. The MP690 Family significantly improves system reliability and accuracy compared to that obtainable with separate ICs or discrete components.

The MP690, MP692, and MP694 are supplied in 8-pin packages and provide four functions:

1) A Reset output during power-up, power-down, and brown out conditions.
2) Battery backup switching for CMOS RAM, CMOS microprocessor or other low power logic.
3) A Reset pulse if the optional watchdog timer has not been toggled within a specified time.
4) A 1.3V threshold detector for power fail warning, low battery detection, or to monitor a power supply other than +5V.

The MP691, MP693 and MP695 are supplied in 16-pin packages and perform all MP690/692 functions, plus:

1) Write protection of CMOS RAM or EEPROM.
2) Adjustable reset and watchdog timeout periods.
3) Separate outputs for indicating a watchdog timeout, backup battery switchover, and low V_{CC}.

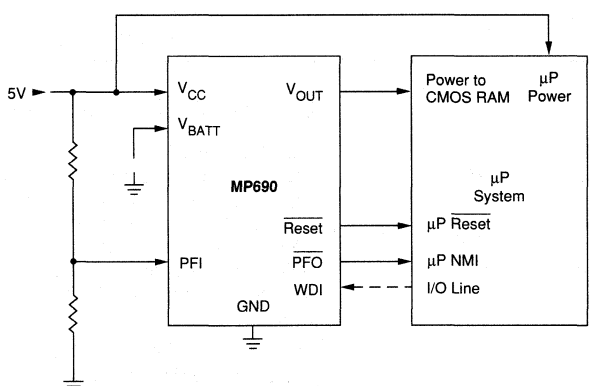
Absolute Maximum Ratings

Terminal Voltage (with respect to GND)	
V_{CC}	-0.3V to 6.0V
V_{BATT}	-0.3V to 6.0V
All other Inputs (Note 1)	-0.3V to (Vout +0.5V)
Input Current	
V_{CC}	200mA
V_{BATT}	50mA
GND	20mA
Output Current	
V_{OUT}short circuit protected	
All Other Outputs	20mA
Rate-of-Rise, V_{BATT}, V_{CC}	100V/µs

Power Dissipation	
8 Pin Plastic DIP	
(Derate 5mW/°C above +70°C)	400mW
8 Pin CERDIP	
(Derate 8mW/°C above +85°C)	500mW
16 Pin Plastic DIP	
(Derate 7mW/°C above +70°C)	600mW
16 Pin Small Outline	
(Derate 7mW/°C above +70°C)	600mW
16 Pin CERDIP	
(Derate 10mW/°C above +85°C)	600mW
Storage Temperature Range	-65°C to +160°C
Lead Temperature (Soldering, 10 seconds)	300°C

Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions above those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum ratings conditions for extended periods may affect device reliability.

Typical Operating Circuit



MP690 Typical Application

Electrical Characteristics

(V_{CC} = full operating range; V_{BATT} = 2.8V; T_A = 25°C, unless otherwise noted.) (Notes 1 and 2)

Parameter	Min	Typ	Max	Unit	Conditions
BATTERY BACKUP SWITCHING					
Operating Voltage Range					
MP690, 691, 694, 695 V_{CC}	4.75		5.5	V	
MP690, 691, 694, 695 V_{BATT}	2.0		4.25		
MP692, 693 V_{CC}	4.5		5.5		
MP692, 693 V_{BATT}	2.0		4.0		
V_{OUT} Output Voltage	V_{CC} - 0.3	V_{CC} - 0.1		V	I_{OUT} = 1mA
	V_{CC} - 0.5	V_{CC} - 0.25			I_{OUT} = 50mA
V_{OUT} in Battery Backup Mode		V_{BATT} - 0.1	V_{BATT} - 0.02	V	I_{OUT} = 100µA, V_{CC}< V_{BATT} - 0.2V
Supply Current (excludes I_{OUT})		2	5	mA	I_{OUT} = 1mA
		3.5	15		I_{OUT} = 50mA
Supply Current in Battery Backup Mode		0.6	1	µA	V_{CC} = 0V, V_{BATT} = 2.8V
Battery Standby Current (+ = Discharge, - = Charge)	-0.1		+0.02	µA	5.5V > V_{CC} > V_{BATT} + 0.2V T_A = 25°C
	-1.0		+0.02		T_A = Full Operating Range
Battery Switchover Threshold V_{CC} - V_{BATT}		70		mV	Power Up
		50			Power Down
Battery Switchover Hysteresis		20		mV	
BATT ON Output Voltage			0.4	V	I_{SINK} = 3.2mA
BATT ON Output Short Circuit Current		25		mA	BATT ON = V_{OUT}
	0.5	1	25	µA	BATT ON = 0V
RESET AND WATCHDOG TIMER					
Reset Voltage Threshold	4.5	4.65	4.75	V	T_A = Full Operating Range MP690, 691, 694, 695
	4.25	4.4	4.5		MP692, 693
Reset Threshold Hysteresis		40		mV	
Reset Timeout Delay					
MP690/691/692/693	35	50	70	ms	Figure 6. OSC SEL High, V_{CC} = 5V
MP694/695	140	200	280		Figure 6. OSC SEL High, V_{CC} = 5V
Watchdog Timeout Period, Internal Oscillator	1.0	1.6	2.25	sec	Long Period, V_{CC} = 5V
	70	100	140	ms	Short Period, V_{CC} = 5V
Watchdog Timeout Period, External Clock	3840		4097	Clock	Long Period
	768		1025	Cycles	Short Period
Minimum WDI Input Pulse Width	200			ns	V_{IL} = 0.4, V_{IH} = 3.5V
$\overline{\text{RESET}}$ and $\overline{\text{LOW LINE}}$ Output Voltage			0.4	V	I_{SINK} = 1.6mA, V_{CC} = 4.25V
	3.5				I_{SOURCE} = 1µA, V_{CC} = 5V
RESET and $\overline{\text{WDO}}$ Output Voltage			0.4	V	I_{SINK} = 1.6µA
	3.5				I_{SOURCE} = 1µA, V_{CC} = 5V
Output Short Circuit Current	1	3	25	µA	$\overline{\text{RESET}}$, RESET, $\overline{\text{WDO}}$, $\overline{\text{LOWLINE}}$
WDI Input Threshold					
Logic Low			0.8	V	V_{CC} = 5V[2]
Logic High	3.5				
WDI Input current		20	50	µA	WDI = V_{OUT}
	-50	-15		µA	WDI = 0V

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Electrical Characteristics (continued)

(V_{CC} = full operating range; V_{BATT} = 2.8V; T_A = 25°C, unless otherwise noted.) (Notes 1 and 2)

Parameter	Min	Typ	Max	Unit	Conditions
POWER FAIL DETECTOR					
PFI Input Threshold	1.2	1.3	1.4	V	V_{CC} = 5V, T_A = Full
PFI Input Current		±0.01	±25	nA	0 To V_{CC} - 0.7V
$\overline{PFO}$ Output Voltage			0.4	V	I_{SINK} = 3.2mA
	3.5				I_{SOURCE} = 1µA
$\overline{PFO}$ Short Circuit Source Current	1	3	25	µA	PFI = 0V, $\overline{PFO}$ = 0V
CHIP ENABLE GATING					
$\overline{CE}$ IN Thresholds			0.8	V	V_{IL}
	3.0				V_{IH}
$\overline{CE}$ IN Pullup Current		3		µA	
$\overline{CE}$ OUT Output Voltage			0.4	V	I_{SINK} = 3.2mA
	V_{out} -1.5				I_{SOURCE} = 3.0mA
	V_{out} -0.05				I_{SOURCE} = 1µA, V_{CC} = 0V
$\overline{CE}$ Propagation Delay		50	200	ns	V_{CC} = 5V
OSCILLATOR					
OSC IN Input Current		±2		µA	
OSC SEL Input Pullup Current		5		µA	
OSC IN Frequency Range	0		250	kHz	OSC SEL = 0V
OSC IN Frequency with External Capacitor		4		kHz	OSC SEL = 0V, C_{OSC} = 47pF

Notes:

1. The input voltage limits on PFI and WDI may be exceeded provided the input current is limited to less than 10mA.
2. WDI is guaranteed to be in the mid-level (inactive) state if WDI is floating and V_{CC} is in the operating voltage range. WDI is internally biased to 38% of V_{CC} with an impedance of approximately 125 kilohms.

Pin Description

Name	Pin		Function
	MP690/692/694	MP691/693/695	
V_{CC}	2	3	The +5V input.
V_{BATT}	8	1	Backup battery input. Connect to Ground if a backup battery is not used.
V_{OUT}	1	2	The higher of V_{CC} or V_{BATT} is internally switched to V_{OUT}. Connect V_{OUT} to V_{CC} if V_{OUT} and V_{BATT} are not used.
GND	3	4	0V ground reference for all signals.
$\overline{RESET}$	7	15	$\overline{RESET}$ goes low whenever V_{CC} falls below either the reset voltage threshold or the V_{BATT} input voltage. The reset threshold is typically 4.65V for the MP690/691/694/695, and 4.4V for the MP692 and MP693. $\overline{RESET}$ remains low for 50ms after V_{CC} returns to 5V (except 200ms in MP694/695). $\overline{RESET}$ also goes low for 50ms if the Watchdog Timer is enabled but not serviced within its timeout period. The $\overline{RESET}$ pulse width can be adjusted as shown in Table 1.
WDI	6	11	The watchdog input, WDI, is a three level input. If WDI remains either high or low for longer than the watchdog timeout period, $\overline{RESET}$ pulses low and $\overline{WDO}$ goes low. The Watchdog Timer is disabled when WDI is left floating or is driven to mid-supply. The timer resets with each transition at the Watchdog Timer Input.
PFI	4	9	PFI is the non-inverting input to the Power Fail Comparator. When PFI is less than 1.3V, $\overline{PFO}$ goes low. Connect PFI to GND when not used. See Figure 1.
$\overline{PFO}$	5	10	$\overline{PFO}$ is the output of the Power Fail Comparator. It goes low when PFI is less than 1.3V. The comparator is turned off and $\overline{PFO}$ goes low when V_{CC} is below V_{BATT}.
$\overline{CE}$ IN		13	The input to the $\overline{CE}$ gating circuit. Connect to GND or V_{OUT} if not used.
$\overline{CE}$ OUT		12	$\overline{CE}$ OUT goes low only when $\overline{CE}$ IN is low and V_{CC} is above the reset threshold (4.65V for MP691and MP695, 4.4V for MP693). See Figure 6.
BATT ON		5	BATT ON goes high when V_{OUT} is internally switched to the V_{BATT} input. It goes low when V_{OUT} is internally switched to V_{CC}. The output typically sinks 7mA and can directly drive the base of an external PNP transistor to increase the output current above the 100mA rating of V_{OUT}.
$\overline{LOW\ LINE}$		6	$\overline{LOW\ LINE}$ goes low when V_{CC} falls below the reset threshold. It returns high as soon as V_{CC} rises above the reset threshold. See Figure 6, Reset Timing.
RESET		16	RESET is an active high output. It is the inverse of $\overline{RESET}$.
OSC SEL		8	When OSC SEL is unconnected or driven high, the internal oscillator sets the reset time delay and watchdog timeout period. When OSC SEL is low, the external oscillator input, OSC IN, is enabled. OSC SEL has a 3µA internal pullup. See Table 1.
OSC IN		7	OSC IN sets the Reset delay timing and Watchdog timeout period when OSC SEL floats or is driven low. The timing can also be adjusted by connecting an external capacitor to this pin. See Figure 8. When OSC SEL is high, OSC IN selects between fast and slow Watchdog timeout periods.
$\overline{WDO}$		14	The Watchdog Output, $\overline{WDO}$, goes low if WDI remains either high or low for longer than the Watchdog timeout period. $\overline{WDO}$ is set high by the next transition at WDI. If WDI is unconnected or at mid-supply, $\overline{WDO}$ remains high. $\overline{WDO}$ also goes high when $\overline{LOW\ LINE}$ goes low.

Typical Applications

MP691, MP693 and MP695

A typical connection for the MP 691/693/695 is shown in Figure 1. CMOS RAM is powered from V_{OUT}. V_{OUT} is internally connected to V_{CC} when 5V power is present, or to V_{BATT} when V_{CC} is less than the battery voltage. V_{OUT} can supply 100mA from V_{CC}, but if more current is required, an external PNP transistor can be added. When V_{CC} is higher than V_{BATT}, the BATT ON output goes low, providing 7mA of base drive for the external transistor. When V_{CC} is lower than V_{BATT}, an internal 500Ω MOSFET connects the backup battery to V_{OUT}. The quiescent current in the battery backup mode is 1µA maximum when V_{CC} is between 0V and V_{BATT} - 700mV.

Reset Output

A voltage detector monitors V_{CC} and generates a $\overline{\text{RESET}}$ output to hold the microprocessor's $\overline{\text{RESET}}$ line low when V_{CC} is below 4.65V (4.4V for MP693). An internal monostable holds $\overline{\text{RESET}}$ low for 50ms* after V_{CC} rises above 4.65V (4.4V for MP693). This prevents repeated toggling of $\overline{\text{RESET}}$ even if the 5V power drops out and recovers with each power line cycle.

The crystal oscillator normally used to generate the clock for microprocessors takes several milliseconds to start. Since most microprocessors need several clock cycles to reset, $\overline{\text{RESET}}$ must be held low until the microprocessor clock oscillator has started. The MP690 Family power-up $\overline{\text{RESET}}$ pulse lasts 50ms* to allow for this oscillator start-up time. The manual reset switch and the 0.1µF capacitor connected to the reset bus can be omitted if manual reset is not needed. An inverted, active high, RESET output is also supplied.

* 200ms for MP695

Power Fail Detector

The MP691/693/695 issues a non-maskable interrupt (NMI) to the microprocessor when a power failure occurs. The +5V power line is monitored via two external resistors connected to the Power Fail Input (PFI). When the voltage at PFI falls below 1.3V, the Power Fail Output ($\overline{\text{PFO}}$) drives the processor's NMI input low. If a Power Fail threshold of 4.8V is chosen, the microprocessor will have the time when V_{CC} falls from 4.8V to 4.65V to save data into RAM. An earlier power fail warning can be generated if the unregulated DCinput of the 5V regulator is available for monitoring.

RAM Write Protection

The MP691/693/695 $\overline{\text{CE}}$ OUT line drives the $\overline{\text{Chip Select}}$ inputs of the CMOS RAM, $\overline{\text{CE}}$ OUT follows $\overline{\text{CE}}$ IN as long as V_{CC} is above the 4.65V (4.4V for MP693) reset threshold. If V_{CC} falls below the reset threshold, $\overline{\text{CE}}$ OUT goes high, independent of the logic level at $\overline{\text{CE}}$ IN. This prevents the microprocessor from writing erroneous data into RAM during power-up, power-down, brownouts, and momentary power interruptions. The $\overline{\text{LOW LINE}}$ output goes low when V_{CC} falls below 4.65V (4.4V for MP693).

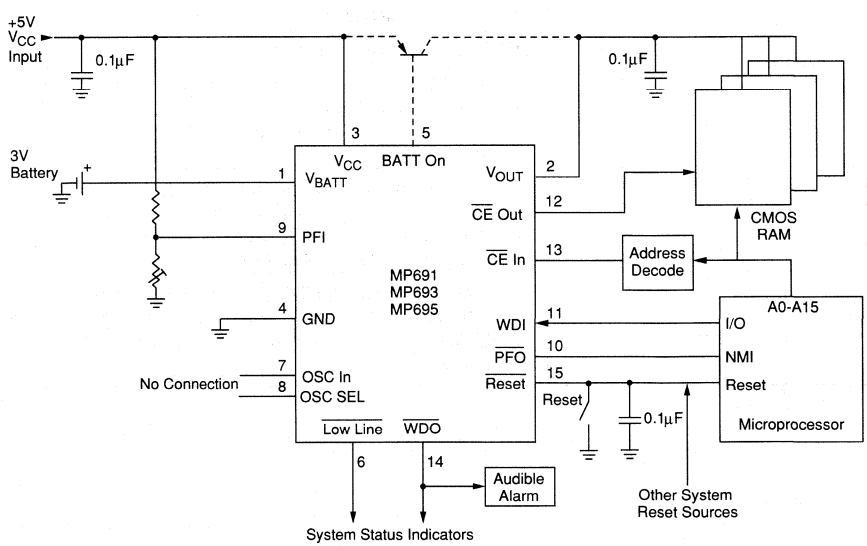


Figure 1. MP691/693/695 Typical Application

Watchdog Timer

The microprocessor drives the WATCHDOG INPUT (WDI) with an I/O line. When OSC IN and OSC SEL are unconnected, the microprocessor must toggle the WDI pin once every 1.6 seconds to verify proper software execution. If a hardware or software failure occurs such that WDI is not toggled, the MP691/693 will issue a 50ms* $\overline{\text{RESET}}$ pulse after 1.6 seconds. This typically restarts the microprocessor's power-up routine. A new $\overline{\text{RESET}}$ pulse is issued every 1.6 seconds until WDI is again strobed.

The WATCHDOG OUTPUT ($\overline{\text{WDO}}$) goes low if the watchdog timer is not serviced within its timeout period. Once $\overline{\text{WDO}}$ goes low, it remains low until a transition occurs at WDI. The watchdog timer feature can be disabled by leaving WDI unconnected. OSC IN and OSC SEL also allow other watchdog timing options, as shown in Table 1 and Figure 8.

MP690, MP692 and MP694

The 8-pin MP690, MP692 and MP694 have most of the features of the MP691, MP693 and MP695. Figure 2 shows the MP690/692/694 in a typical application. Operation is much the same as with the MP691/693/695 (Figure 1) but in this case the Power Fail Input (PFI) monitors the unregulated input to the 7805 regulator. The MP690/694 $\overline{\text{RESET}}$ output goes low when V_{CC} falls below 4.65V. The $\overline{\text{RESET}}$ output of the MP692 goes low when V_{CC} drops below 4.4V.

The current consumption of the battery-backed-up power bus must be less than 100mA. The MP690/692/694 does not have a BATT ON output to drive an external transistor. The MP690/692/694 also does not include chip enable gating circuitry that is available on the MP691/693/695. In many systems though, $\overline{\text{CE}}$ gating is not needed since a low input to the microprocessor $\overline{\text{RESET}}$ line prevents the processor from writing to RAM during power-up and power-down transients.

The MP690/692/694 watchdog timer has a fixed 1.6 second time-out period. If WDI remains either low or high for more than 1.6 seconds, a $\overline{\text{RESET}}$ pulse is sent to the microprocessor. The watchdog timer is disabled if WDI is left floating.

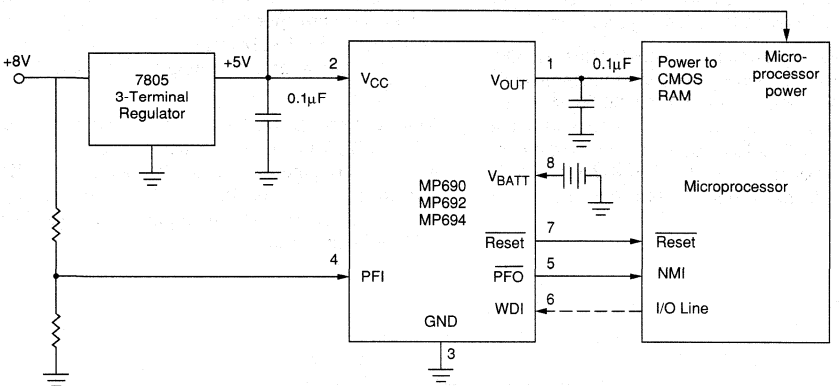


Figure 2. MP690/692/694 Typical Application

Detailed Description

Battery-Switchover and V_{OUT}

The battery switchover circuit compares V_{CC} to the V_{BATT} input, and connects V_{OUT} to whichever is higher. Switchover occurs when V_{CC} is 50mV greater than V_{BATT} as V_{CC} falls, and when V_{CC} is 70mV more than V_{BATT} as V_{CC} rises (see Figure 4). The switchover comparator has 20mV of hysteresis to prevent repeated, rapid switching if V_{CC} falls very slowly or remains nearly equal to the battery voltage.

When V_{CC} is higher than V_{BATT}, V_{CC} is internally switched to V_{OUT} via a low saturation PNP transistor. V_{OUT} has 100mA output current capability and thermal shutdown short circuit protection. Use an external PNP pass transistor in parallel with the internal transistor if the output current requirement at V_{OUT} exceeds 100mA or if a lower V_{CC}-V_{OUT} voltage differential is desired. The BATT ON output (MP691/693/695 only) can directly drive the base of the external transistor.

It should be noted that the MP690/691/692/693/694/695 need only supply the average current drawn by the CMOS RAM if there is adequate filtering. Many RAM data sheets specify a 75mA maximum supply current, but this peak current spike lasts only 100ns. A 0.1µF bypass capacitor at V_{OUT} supplies the high instantaneous current, while V_{OUT} need only supply the average load current, which is much less. A capacitance of 0.1µF or greater must be connected to the V_{OUT} terminal to ensure stability.

A 500 ohm MOSFET connects the V_{BATT} input to V_{OUT} during battery backup. This MOSFET has very low input-to-output differential (dropout voltage) at the low current levels required for battery backup of CMOS RAM or other low power CMOS circuitry. When V_{CC} equals V_{BATT}, the supply current is typically 12µA. When V_{CC} is between 0V and (V_{BATT}-700mV), the typical supply current is only 600nA typical, 1µA maximum.

The MP690/691/694/695 operates with battery voltages from 2.0V to 4.25V while the MP692/693 operates with battery voltages from 2.0V to 4.0V. High value capacitors, either standard electrolytic or the farad-size double layer capacitors, can also be used for short-term memory backup. The charging resistor for both capaci-

tors and rechargeable batteries should be connected to V_{OUT} since this eliminates the discharge path that exists if the resistor is connected to V_{CC}.

A small charging current of typically 10nA (5µA max) flows out of the V_{BATT} terminal. This current varies with the amount of current that is drawn from V_{OUT} but its polarity is such that the backup battery is always slightly charged and is never discharged while V_{CC} is in its operating voltage range. This extends the shelf life of the backup battery by compensating for its self-discharging current. Also note that this current poses no problem when lithium batteries are used for backup since the maximum charging current (5µA) is safe for even the smallest lithium cells.

If the battery-switchover section is not used, connect V_{BATT} to GND and connect V_{OUT} to V_{CC}. Table 2 shows the status of the input and output in the low power battery backup mode.

Reset Output

$\overline{\text{RESET}}$ is an active low output which goes low whenever V_{CC} falls below 4.5V (MP690/691/694/695) or 4.25V (MP692/693). It will remain low until V_{CC} rises above 4.75V (MP 690/691/694/695) or 4.5V (MP692/693) for 50 milliseconds.* (See Figures 5 and 6.)

The guaranteed minimum and maximum thresholds of the MP 690/691/694/695 are 4.5V and 4.75V, while the guaranteed thresholds of the MP692/693 are 4.25V and 4.5V. The MP690/691/694/695 is compatible with 5V supplies with a +10%, -5% tolerance while the MP692/693 is compatible with 5V ±10% supplies. The reset threshold comparator has approximately 50mV of hysteresis, with a nominal threshold of 4.65V in the MP690/691/694/695, and 4.4V in the MP692/693.

The response time of the reset voltage comparator is about 100µs. VCC should be bypassed to ensure that glitches do not activate the $\overline{\text{RESET}}$ output.

$\overline{\text{RESET}}$ also goes low if the Watchdog Timer is enabled and WDI remains either high or low longer than the watchdog timeout period. $\overline{\text{RESET}}$ has an internal 3µA pullup and can either connect to an open collector Reset bus or directly drive a CMOS gate without an external pullup resistor.

$\overline{\text{CE}}$ Gating and RAM Write Protection

The MP691, MP693 and MP695 use two pins to control the $\overline{\text{Chip Enable}}$ or $\overline{\text{Write}}$ inputs of CMOS RAMs. When V_{CC} is +5V, $\overline{\text{CE}}$ OUT is a buffered replica of $\overline{\text{CE}}$ IN, with a 50ns propagation delay. If V_{CC} input falls below 4.65V (4.5V min, 4.75V max), an internal gate forces $\overline{\text{CE}}$ OUT high, independent of $\overline{\text{CE}}$ IN. The MP693 $\overline{\text{CE}}$ OUT goes high whenever V_{CC} is below 4.4V (4.25V min, 4.5V max). The $\overline{\text{CE}}$ output of both devices is also forced high when V_{CC} is less than V_{BATT}. (See Figure 5.)

$\overline{\text{CE}}$ OUT typically drives the $\overline{\text{CE}}$, $\overline{\text{CS}}$, or $\overline{\text{Write}}$ input of battery backed up CMOS RAM. This ensures the integrity of the data in memory by preventing write operations when V_{CC} is at an invalid level. Similar protection of EEPROMs can be achieved by using the $\overline{\text{CE}}$ OUT to drive the Store or Write inputs of an EEPROM, EAROM, or NOVRAM.

If the 50ns typical propagation delay of $\overline{\text{CE}}$ OUT is too long, connect $\overline{\text{CE}}$ IN to GND and use the resulting $\overline{\text{CE}}$ OUT to control a high speed external logic gate. A second alternative is to AND the $\overline{\text{LOW LINE}}$ output with the $\overline{\text{CE}}$ or $\overline{\text{WR}}$ signal. An external logic gate and the $\overline{\text{RESET}}$ output of the MAX690/692/964 can also be used for CMOS RAM write protection.

* 200ms for MP694 and MP695

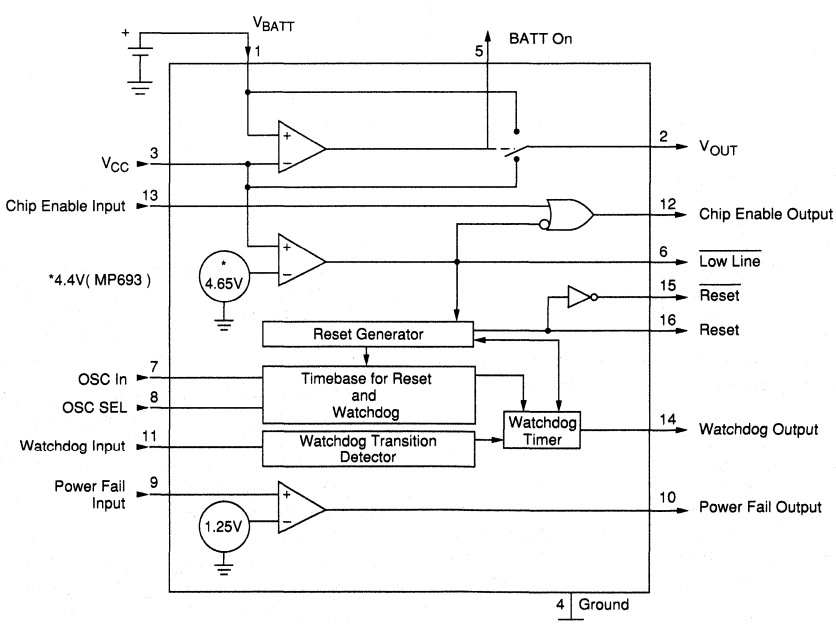


Figure 3. MP 691/693/695 Block Diagram

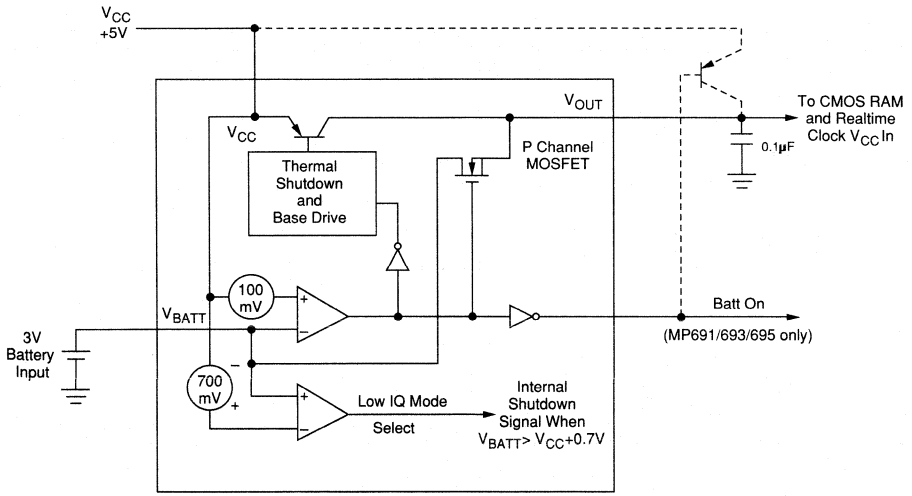


Figure 4. Battery–Switchover Block Diagram

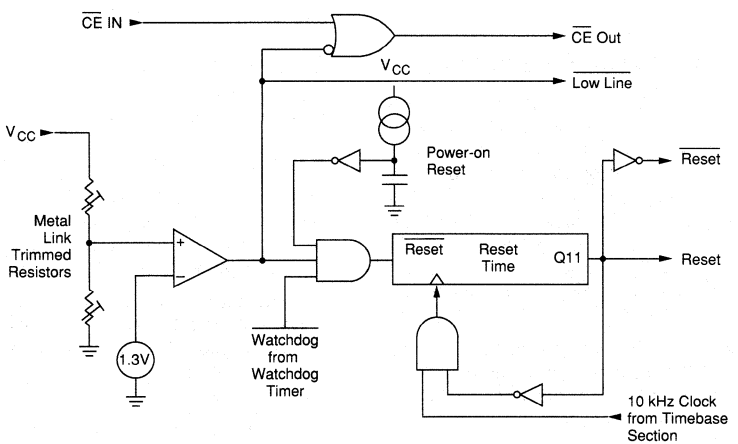
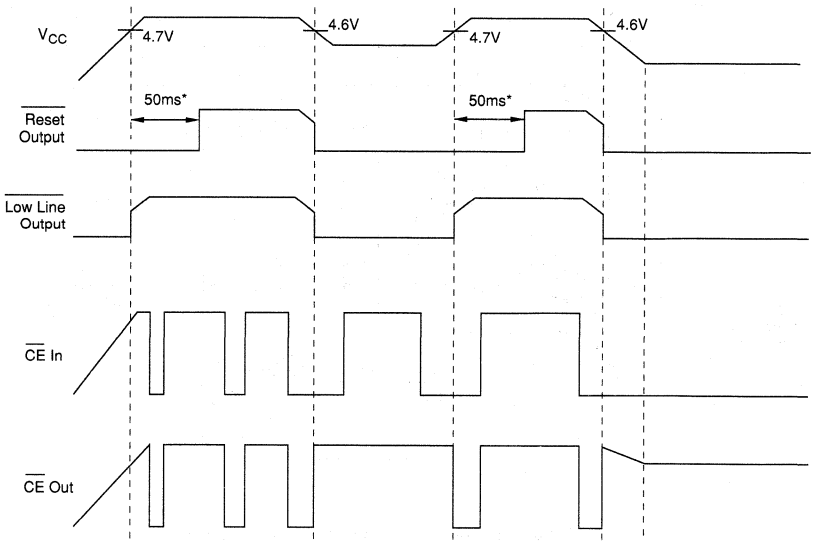


Figure 5. Reset Block Diagram



*200ms for MP694 and MP695

Figure 6. Reset Timing

1.3V Comparator and Power Fail Warning

The Power Fail Input (PFI) is compared to an internal 1.3V reference. The Power Fail Output ($\overline{PFO}$) goes low when the voltage at PFI is less than 1.3V. Typically PFI is driven by an external voltage divider which senses either the unregulated DC input to the system's 5V regulator or the regulated 5V output. The voltage divider ratio can be chosen such that the voltage at PFI falls below 1.3V several milliseconds before the +5V supply falls below 4.75V. $\overline{PFO}$ is normally used to interrupt the microprocessor so that data can be stored in RAM before V_{CC} falls below 4.75V and the $\overline{RESET}$ output goes low (4.5V for MP692/693).

The Power Fail Detector can also monitor the backup battery to warn of a low battery condition. To conserve battery power, the Power Fail Detector comparator is turned off and $\overline{PFO}$ is forced low when V_{CC} is lower than the V_{BATT} input voltage.

Watchdog Timer and Oscillator

The watchdog circuit monitors the activity of the microprocessor. If the microprocessor does not toggle the Watchdog Input (WDI) within the selected timeout period, a 50 millisecond* $\overline{RESET}$ pulse is generated. Since many systems cannot service the watchdog timer immediately after a reset, the MP691/693/695 has a longer timeout period after a reset is issued. The normal timeout period becomes effective following the first transition of WDI after $\overline{RESET}$ has gone high. The watchdog timer is restarted at the end of Reset, whether the Reset was caused by lack of activity on WDI or by V_{CC} falling below the reset threshold. If WDI remains either high or low, reset pulses will be issued every 1.6 seconds. The watchdog monitor can be deactivated by floating the Watchdog Input (WDI).

The Watchdog Output ($\overline{WDO}$, MP691/693/695 only) goes low if the watchdog timer "times out", and it remains low until set high by the next transition on the watchdog input. $\overline{WDO}$ is also set high when V_{CC} goes below the reset threshold.

The watchdog timeout period is fixed at 1.6 seconds and the reset pulse width is fixed at 50ms* on the 8-pin MP690, MP692 and MP694. The MP691, MP693 and MP695 allow these times to be adjusted per Table 1. Figure 8 shows various oscillator configurations.

The internal oscillator is enabled when OSC SEL is high or floating. In this mode, OSC IN selects between the 1.6 second and 100ms watchdog timeout periods. In either case, immediately after a reset, the timeout period is 1.6 seconds. This gives the microprocessor time to reinitialize the system. If OSC IN is low, then the 100ms watchdog period becomes effective after the first transition of WDI. The software should be written such that the I/O port driving WDI is left in its power-up reset state until the initialization routines are completed and the microprocessor is able to toggle WDI at the minimum watchdog timeout period to 70ms.

* 200ms for MP694 and MP695

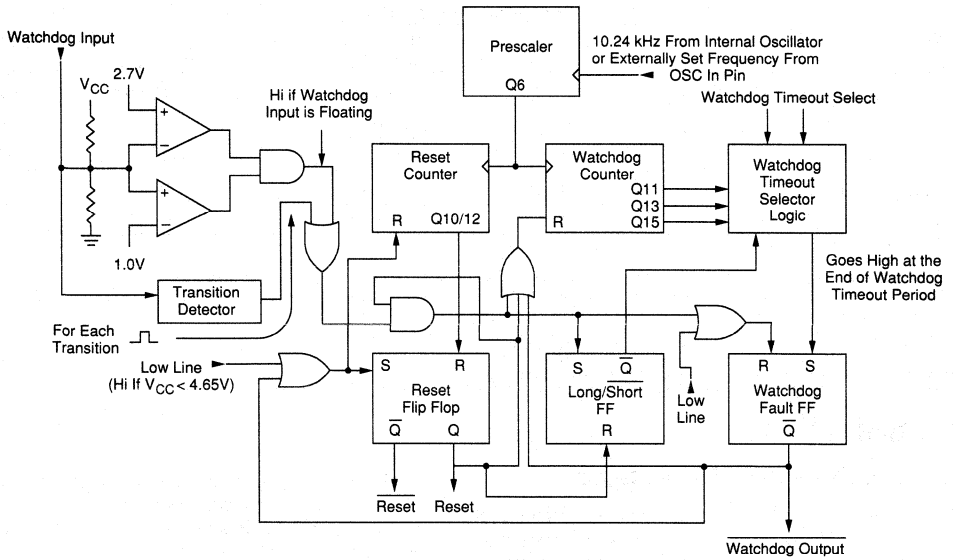


Figure 7. Watchdog Timer Block Diagram

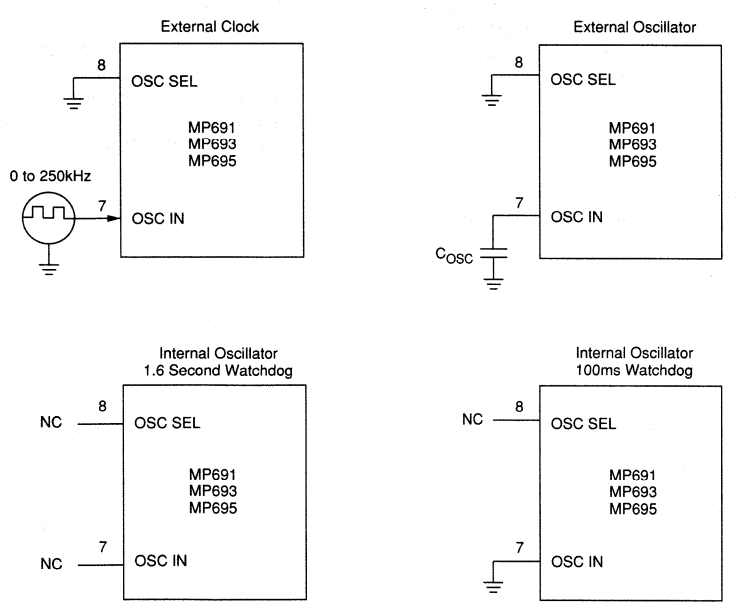


Figure 8. Oscillator Circuits

Table 1. MP691, MP693 and MP695 Reset Pulse Width and Watchdog Timeout Selections

OSC SEL	OSC IN	Watchdog Timeout Period		Reset Timeout Period	
		Normal	Immediately After Reset	MP691/693	MP695
Low	External Clock Input	1024 clks	4096 clks	512 clks	2048 clks
Low	External Capacitor	$\frac{400ms}{47pF} \times C$	$\frac{1.6\ sec}{47pF} \times C$	$\frac{200ms}{47pF} \times C$	$\frac{800ms}{47pF} \times C$
High/Floating	Low	100ms	1.6 sec	50ms	200ms
High/Floating	High / Floating	1.6 sec	1.6 sec	50ms	200ms

Notes:
1. The MP690 watchdog timeout period is fixed at 1.6 seconds nominal; the MP690 Reset pulse width is fixed at 50ms nominal.
2. When the MP691 OSC SEL pin is low, OSC IN can be driven by an external clock signal or an external capacitor can be connected between OSC IN and GND. The nominal internal oscillator frequency is 10.24kHz.
   The nominal oscillator frequency with external capacitor is $F_{OSC\ (Hz)} = \frac{184,000}{C(pF)}$
3. See Electrical Characteristics Table for minimum and maximum timing values.

Application Hints

Other Uses of the Power Fail Detector

In Figure 9, the Power Fail Detector is used to initiate a system reset when V_{CC} falls to 4.85V. Since the threshold of the Power Fail Detector is not as accurate as the onboard Reset voltage detector, a trimpot must be used to adjust the voltage detection threshold. Both the PFO and $\overline{RESET}$ outputs have high sink current capability and only 10µA of source current drive. This allows the two outputs to be connected directly to each other in a "wired or" fashion.

The overvoltage detector circuit in Figure 10 resets the microprocessor whenever the nominal 5V V_{CC} is above 5.5V. The battery monitor circuit (Figure 11) shows the status of the memory backup battery. If desired, the $\overline{CE}$ OUT can be used to apply a test load to the battery. Since $\overline{CE}$ OUT is forced high during the battery backup mode, the test load will not be applied to the battery while it is in use,even if the microprocessor is not powered.

Adding Hysteresis to the Power Fail Comparator

Since the power fail comparator circuit is non-inverting, hysteresis can be added by connecting a resistor between the PFO output and the PFI input as shown in Figure 12. When PFO is low, resistor R3 sinks current from the summing junction at the PFI pin. When PFO is high, the series combination of R3 and R4 source current into the PFI summing junction.

Alternate Watchdog Input Drive Circuits

The Watchdog feature can be enabled and disabled under program control by driving WDI with a 3-state buffer (Figure 13). The drawback to this circuit is that a software fault may erroneously 3-state the buffer, thereby preventing the MP690 from detecting that the microprocessor is no longer working. In most cases, a better method is to extend the watchdog period rather than disabling the watchdog. See Figure 14. When the control input is high, the OSC SEL pin is low and the watchdog timeout is set by the external capacitor. A 0.01µF capacitor sets a watchdog timeout delay of 100 seconds. When the control input is low, the OSC SEL pin is driven high, selecting the internal oscillator. The 100ms or the 1.6 sec period is chosen, depending on which diode in Figure 14 is used.

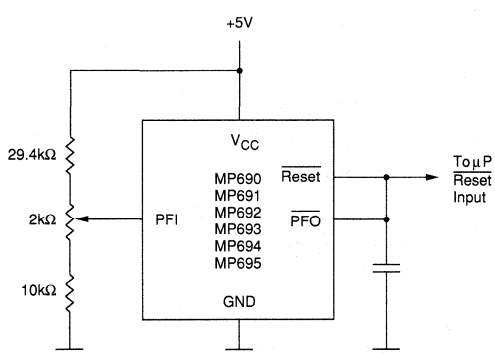


Figure 9. Externally Adjustable V_{CC} Reset Threshold

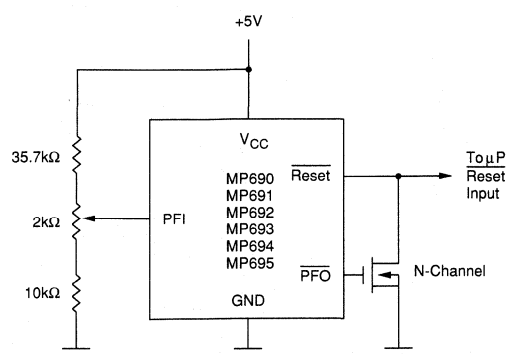


Figure 10. Reset on Overvoltage or Undervoltage

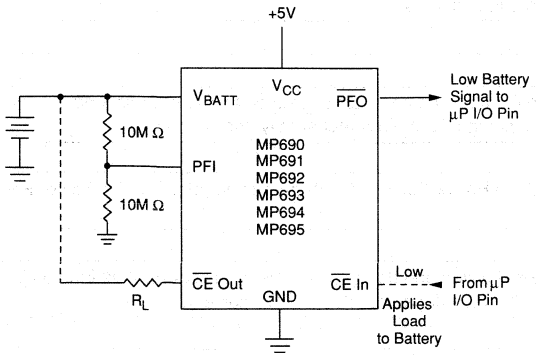


Figure 11. Backup Battery Monitor with Optional Test Load

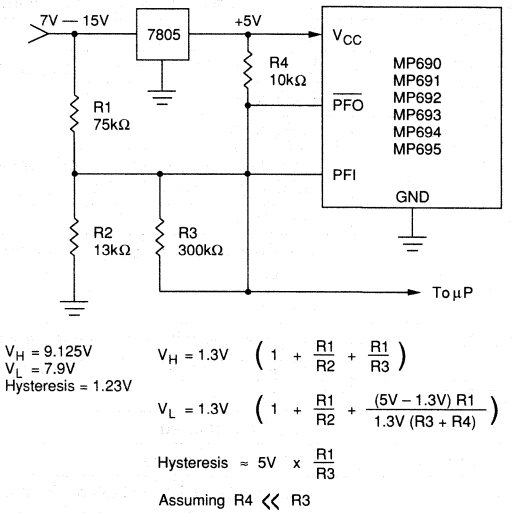


Figure 12. Adding Hysteresis to the Power Fail Voltage Comparator

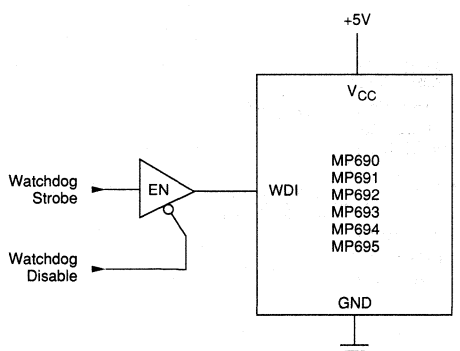


Figure 13. Disabling the Watchdog Under Program Control

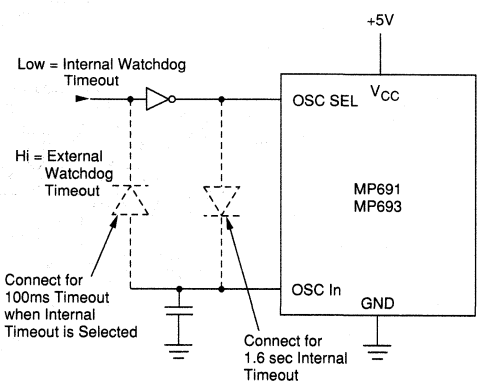


Figure 14. Selecting Internal or External Watchdog Timeout

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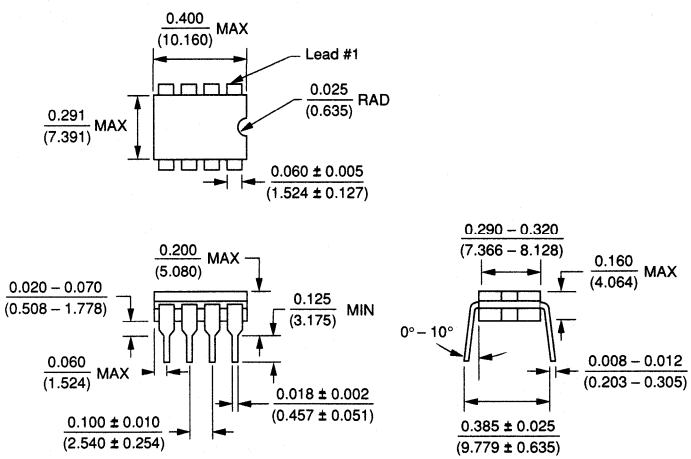
Table 2. Input and Output Status In Battery Backup Mode

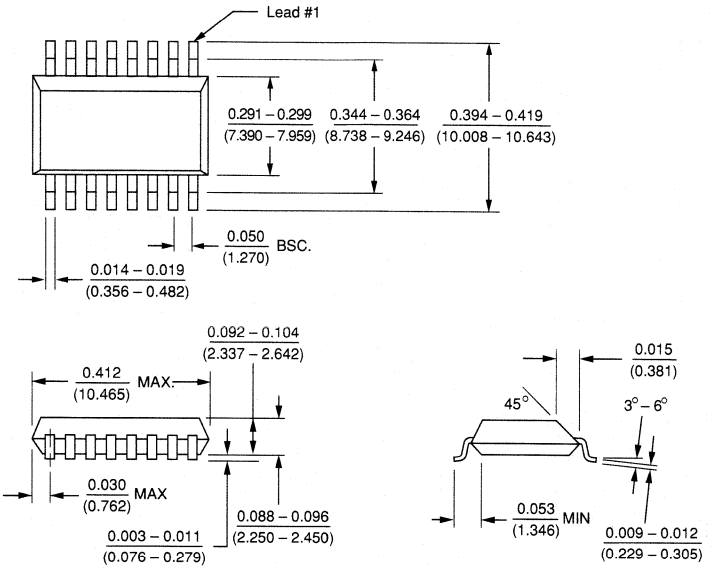
V_{BATT}, V_{OUT}	V_{BATT} is connected to V_{OUT} via internal MOSFET.
$\overline{RESET}$	Logic low.
RESET	Logic high. The open circuit output voltage is equal to V_{OUT}.
$\overline{LOW\ LINE}$	Logic low.
BATT ON	Logic high.
WDI	WDI is internally disconnected from its internal pullup and does not source or sink current as long as its input voltage is between GND and V_{OUT}. The input voltage does not affect supply current.
$\overline{WDO}$	Logic high.
PFI	The Power Fail Comparator is turned off and the Power Fail Input voltage has no effect on the Power Fail Output.
$\overline{PFO}$	Logic low.
$\overline{CE}$ IN	$\overline{CE}$ IN is internally disconnected from its internal pullup and does not source or sink current as long as its input voltage is between GND and V_{OUT}. The input voltage does not affect supply current.
$\overline{CE}$ OUT	Logic high.
OSC IN	OSC IN is ignored.
OSC SEL	OSC SEL is ignored.
V_{CC}	Approximately 12µA is drawn from the V_{BATT} input when V_{CC} is between V_{BATT} + 100mV and V_{BATT} - 700mV. The supply current is 1µA maximum when V_{CC} is less than V_{BATT} - 700mV.

Package Information



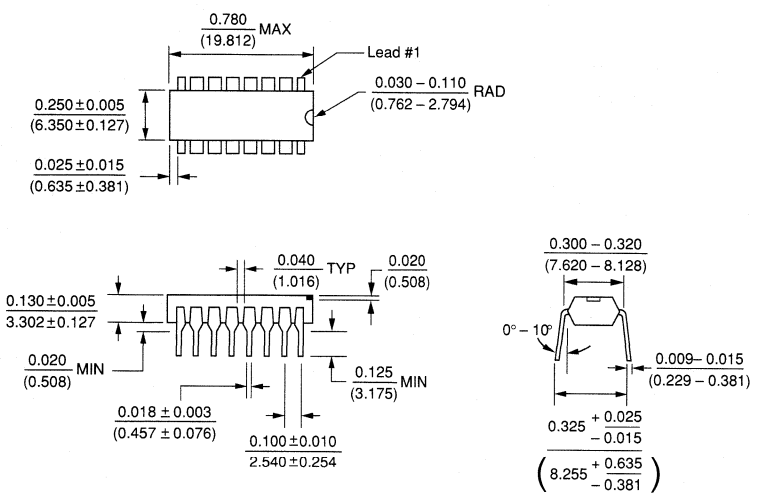
8 LEAD CERDIP (D)

θ_{ja} = 125°C/W
θ_{jc} = 55°C/W



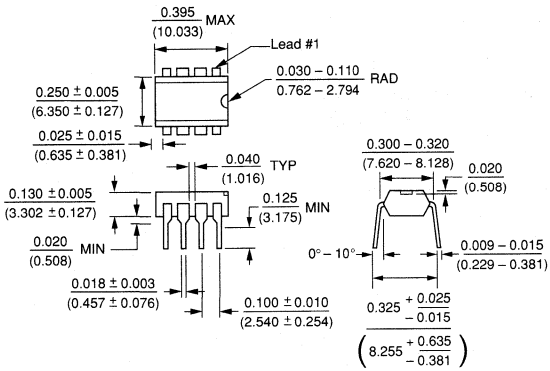
16 Lead Small Outline, Wide (WG)

θ_{ja} = 105° C/W
θ_{jc} = 60° C/W



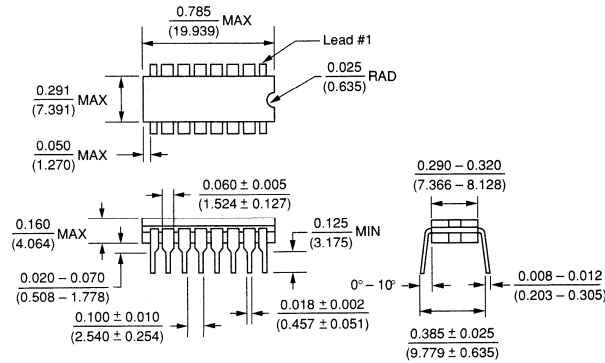
16 Lead Plastic DIP (P)

θ_{ja} = 100° C/W
θ_{jc} = 60°C/W



8 LEAD PLASTIC DIP (P)

θ_{ja} = 120° C/W
θ_{jc} = 70° C/W

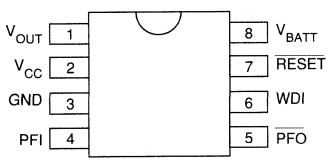


16 LEAD CERDIP (D)

θ_{ja} = 100° C/W
θ_{jc} = 50° C/W

Pin Configuration

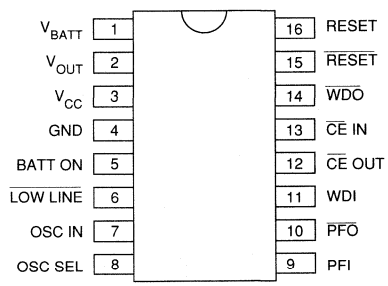
MP690, MP692 and MP694



top view

8-pin DIP

MP691, MP693 and MP695



top view

16-pin DIP

Microprocessor Supervisory Circuits

Ordering Information

Device	Temperature Range	Package	Order No.
MP696	0°C to + 70°C	16 Lead Plastic DIP	MP696P
	0°C to + 70°C	16 Lead Wide SO	MP696WG
	-40°C to + 85°C	16 Lead Plastic DIP	MP696MP
	-40°C to + 85°C	16 Lead CERDIP	MP696MD
	-40°C to + 85°C	16 Lead Wide SO	MP696MWG
	-55°C to + 125°C	16 Lead CERDIP	RCMP696D
MP697	0°C to + 70°C	16 Lead Plastic DIP	MP697P
	0°C to + 70°C	16 Lead Wide SO	MP697WG
	-40°C to + 85°C	16 Lead Plastic DIP	MP697MP
	-40°C to + 85°C	16 Lead CERDIP	MP697MD
	-40°C to + 85°C	16 Lead Wide SO	MP697MWG
	-55°C to + 125°C	16 Lead CERDIP	RCMP697D

Features

- ☐ Adjustable Low Line Monitor and Power Down Reset
- ☐ Power OK/Reset Time Delay
- ☐ Watchdog Timer-100ms, 1.6 sec, or adjustable
- ☐ Minimum Component Count
- ☐ 1uA Standby Current
- ☐ Battery Backup Power Switching (MP696)
- ☐ Onboard Gating of Chip Enable Signals (MP697)
- ☐ Separate Monitor for Power Fail or Low Battery Warning

Applications

- ☐ Computers
- ☐ Controllers
- ☐ Intelligent Instruments
- ☐ Automotive Systems
- ☐ Critical µP Power Monitoring

General Description

The MP696/697 supervisory circuits reduce the complexity and number of components required for power supply monitoring and battery control functions in microprocessor systems. These include uP reset and backup-battery switchover, watchdog timer, CMOS RAM write protection, and power-failure warning. The MP696/697 significantly improves system reliability and accuracy compared to that obtained with separate ICs or discrete components.

The MP696 and MP697 are supplied in 16 pin packages and perform six functions:

1. A Reset output during power-up, power-down and brownout conditions. The threshold for this "low line" reset is adjustable by an external voltage divider.
2. A Reset pulse if the optional watchdog timer has not been toggled within a specified time.
3. Individual outputs for low line and watchdog fault conditions.
4. The Reset time may be left at its default value of 50 ms. or may be varied with an external capacitor or clock pulses.
5. A separate 1.3 volt threshold detector for power fail warning, low battery detection, or to monitor a power supply other than V_{CC}.

The MP696 also has battery backup switching for CMOS RAM, CMOS microprocessor, or other low power logic.

The MP697 lacks battery backup switching, but has write protection pins (CE_{IN} and CE_{OUT}) for CMOS RAM or EPROM. In addition, it consumes less than 250 microamperes.

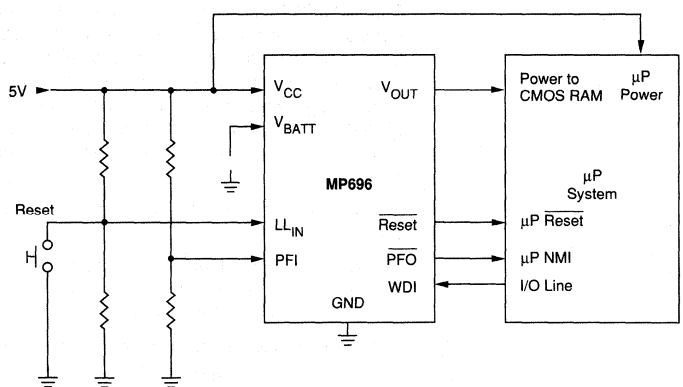
Absolute Maximum Ratings

Terminal Voltage (with respect to GND)	
V_{CC}	-0.3V to 6.0V
V_{BATT}	-0.3V to 6.0V
All Other Inputs (Note 1)	-0.3V to (V_{OUT} +0.5V)
Input Current	
V_{CC}	200mA
V_{BATT}	50mA
GND	20mA
Output Current	
V_{OUT}	Short Circuit Protected
All Other Outputs	20mA

Rate-of-Rise, V_{BATT}, V_{CC}	100V/µs
Power Dissipation	
16 Pin Plastic DIP	
(Derate 7mW/°C above +70°C)	600mW
16 Pin Small Outline	
(Derate 7mW/°C above +70°C)	600mW
16 Pin CERDIP	
(Derate 10mW/°C above +85°C)	600mW
Storage Temperature Range	-65°C to +160°C
Lead Temperature (Soldering, 10 seconds)	300°C

Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions above those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Typical Operation Circuit



MP696 Typical Application

Electrical Characteristics

(V_{CC} = full operating range; V_{BATT} = 2.8V; T_A = 25°C, unless otherwise noted.) (Notes 1, 2 and 3)

Parameter	Min	Typ	Max	Unit	Conditions
Operating Voltage Range					
MP696, V_{CC}	3.0		5.5	V	T_A = Full
MP696, V_{BATT}	2.0		V_{CC} -0.3		
MP697, V_{CC}	3.0		5.5		
Supply Current (MP697)		160	300	µA	T_A = Full
BATTERY BACKUP SWITCHING (MP696)					
V_{OUT} Output Voltage		V_{CC}- 0.1	V_{CC}- 0.3	V	I_{OUT} = 1mA, T_A = Full
		V_{CC}- 0.25	V_{CC}- 0.5		I_{OUT} = 50mA, T_A = Full
V_{OUT} in Battery Backup Mode	V_{BATT}- 0.1	V_{BATT}- 0.02		V	I_{OUT} = 100µA, V_{CC}< V_{BATT} - 0.2V, T_A = Full
Supply Current (excludes I_{OUT})		1.5	4	mA	I_{OUT} = 1mA
		2.5	7		I_{OUT} = 50mA
Supply Current in Battery Backup Mode		0.6	1	µA	V_{CC} = 0V, V_{BATT} = 2.8V, T_A = 25°C
			10		V_{CC} = 0V, V_{BATT} = 2.8V, T_A = Full
Battery Standby Leakage Current	-100		+20	nA	5.5V > V_{CC} > V_{BATT} + 0.3V, T_A = 25°C
	-1		+0.02	µA	5.5V > V_{CC} > V_{BATT} + 0.3V, T_A = Full
Battery Switchover Threshold		70		mV	Power Up
V_{CC} - V_{BATT}		50			Power Down
Battery Switchover Hysteresis		20		mV	
BATT ON Output Voltage			0.4	V	I_{SINK} = 1.6mA
BATT ON Output Short Circuit Current		7		mA	BATT ON = V_{OUT}
	0.5	2.5	25	µA	BATT ON = V_{OUT}, V_{CC} =0V
RESET AND WATCHDOG TIMER					
Low Line Voltage Threshold (LL_{IN})	1.25	1.30	1.35	V	V_{CC} = 5V, +3V, T_A = Full
Reset Timeout Delay	35	50	70	ms	Fig. 6. OSC SEL High, V_{CC} = 5V
Watchdog Timeout Period, Internal Oscillator	1.0	1.6	2.25	sec	Long Period, V_{CC} = 5V
	70	100	140	ms	Short Period, V_{CC} = 5V
Watchdog Timeout Period, External Clock	4032		4097	Clock	Long Period
	960		1025	Cycles	Short Period
Minimum WDI Input Pulse Width	200			ns	V_{IL} = 0.4, V_{IH} = 3.5V, V_{CC} = 5V
$\overline{\text{RESET}}$ and RESET Output Voltage[3]			0.4	V	I_{SINK} = 400µA, V_{CC} = 2V, V_{BATT} = 0
			0.4		I_{SINK} = 1.6mA, 3V < V_{CC} < 5.5V
	3.5				I_{SOURCE} = 1µA, V_{CC} = 5V
$\overline{\text{LOW LINE}}$ and $\overline{\text{WDO}}$ Output Voltage			0.4	V	I_{SINK} = 800µA, T_A = Full
	3.5				I_{SOURCE} = 1µA, V_{CC} = 5V , T_A = Full
Output Short Circuit Current	1	3	25	µA	$\overline{\text{RESET}}$, RESET, $\overline{\text{WDO}}$, $\overline{\text{LOWLINE}}$
WDI Input Threshold — Logic Low			0.8	V	V_{CC} = 5V [2]
WDI Input Threshold — Logic High (MP696)	3.5				
WDI Input Threshold — Logic High (MP697)	3.8				
WDI Input Current		20	50	µA	WDI = V_{OUT}
	-50	-15			WDI = 0V

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Electrical Characteristics (continued)

(V_{CC} = full operating range; V_{BATT} = 2.8V; T_A = 25°C, unless otherwise noted.) (Notes 1, 2 and 3)

Parameter	Min	Typ	Max	Unit	Conditions
POWER FAIL DETECTOR					
PFI Input Threshold	1.2	1.3	1.4	V	V_{CC} =3V, 5V
PFI -LL_{IN} Threshold Difference		±15	±50	mV	V_{CC} =3V, 5V
PFI Input Current		±0.01	±25	nA	0 To V_{CC} - 0.7V
LL_{IN} Input Current	-25	±0.01	25	nA	MP697
	-500	±0.01	25		MP696
$\overline{PFO}$ Output Voltage			0.4	V	I_{SINK} = 1.6mA
	3.5				I_{SOURCE} = 1µA, V_{CC} =5V
$\overline{PFO}$ Short Circuit Source Current	1	3	25	µA	PFI = 0V, $\overline{PFO}$ = 0V
CHIP ENABLE GATING (MP697)					
$\overline{CE}$ IN Thresholds			0.8	V	V_{IL}
	3.0				V_{IH}, V_{CC} = 5V
$\overline{CE}$ IN Pullup Current		3		µA	
$\overline{CE}$ OUT Output Voltage			0.4	V	I_{SINK} = 1.6mA
	V_{CC} -0.5				I_{SOURCE} = 800µA
	V_{CC} -0.05				I_{SOURCE} = 1µA, V_{CC} = 0V
$\overline{CE}$ Propagation Delay		80	150	ns	V_{CC} = 5V
OSCILLATOR					
OSC IN Input Current		±2		µA	
OSC SEL Input Pullup Current		5		µA	
OSC IN Frequency Range	0		250	kHz	OSC SEL = 0V
OSC IN Frequency with External Capacitor		4		kHz	OSC SEL = 0V, C_{OSC} = 47pF

Notes:

1. The input voltage limits on PFI and WDI may be exceeded providing the input current is limited to less than 10mA.
2. WDI is guaranteed to be in the mid-level (inactive) state if WDI is floating and V_{CC} is in the operating voltage range. WDI is internally biased to 38% of V_{CC} with an impedance of approximately 125 kilohms.

Pin Description

Name	Pin		Function
	MP696	MP697	
V_{CC}	3	3	The +5V input.
V_{BATT}	1		Backup battery input. Connect to Ground if a backup battery is not used.
V_{OUT}	2		The higher of V_{CC} or V_{BATT} is internally switched to V_{OUT}. Connect V_{OUT} to V_{CC} if V_{OUT} and V_{BATT} are not used.
GND	4	5	0V ground reference for all signals.
$\overline{RESET}$	15	15	$\overline{RESET}$ goes low whenever LL_{IN} falls below 1.3 volts or V_{CC} falls below the V_{BATT} input voltage. $\overline{RESET}$ remains low for 50ms after LL_{IN} goes above 1.3 volts. $\overline{RESET}$ also goes low for 50ms if the Watchdog Timer is enabled but not serviced within its timeout period. The $\overline{RESET}$ pulse width can be adjusted as shown in Table 1.
WDI	11	11	The watchdog input, WDI, is a three level input. If WDI remains either high or low for longer than the watchdog timeout period, $\overline{RESET}$ pulses low and $\overline{WDO}$ goes low. The Watchdog Timer is disabled when WDI is left floating or is driven to mid-supply. The timer resets with each transition at the Watchdog Timer Input.
PFI	9	9	PFI is the non-inverting input to the Power Fail Comparator. When PFI is less than 1.3V, $\overline{PFO}$ goes low. Connect PFI to GND when not used. See Figure 1.
$\overline{PFO}$	10	10	$\overline{PFO}$ is the output of the Power Fail Comparator. It goes low when PFI is less than 1.3V. The comparator is turned off and $\overline{PFO}$ goes low when V_{CC} is below V_{BATT}.
$\overline{CE}$ IN		13	The input to the $\overline{CE}$ gating circuit. Connect to GND or V_{OUT} if not used.
$\overline{CE}$ OUT		12	$\overline{CE}$ OUT goes low only when $\overline{CE}$ IN is low and LL_{IN} is above 1.3V. See Figure 5.
BATT ON	5		BATT ON goes high when V_{CC} is internally switched to the V_{BATT} input. It goes low when V_{OUT} is internally switched to V_{CC}. The output typically sinks 7mA and can directly drive the base of an external PNP transistor to increase the output current above the 100mA rating of V_{OUT}.
$\overline{LOW\ LINE}$	6	6	$\overline{LOW\ LINE}$ goes low when LL_{IN} falls below 1.3 volts. It returns high as soon as LL_{IN} rises above 1.3 volts. See Figure 5, Reset Timing.
RESET	16	16	RESET is an active high output. It is the inverse of $\overline{RESET}$.
OSC SEL	8	8	When OSC SEL is unconnected or driven high, the internal oscillator sets the reset time delay and watchdog timeout period. When OSC SEL is low, the external oscillator input, OSC IN, is enabled. OSC SEL has a 3µA internal pullup. See Table 1.
OSC IN	7	7	OSC IN sets the Reset delay timing and Watchdog timeout period when OSC SEL floats or is driven low. The timing can also be adjusted by connecting an external capacitor to this pin. See Figure 7. When OSC SEL is high, OSC IN selects between fast and slow Watchdog timeout periods.
$\overline{WDO}$	14	14	The Watchdog Output, $\overline{WDO}$, goes low if WDI remains either high or low for longer than the Watchdog timeout period. $\overline{WDO}$ is set high by the next transition at WDI. If WDI is unconnected or at mid-supply, $\overline{WDO}$ remains high. $\overline{WDO}$ also goes high when $\overline{LOW\ LINE}$ goes low.
NC	12	2	NO CONNECTION. Leave this pin open.
LL_{IN}	13	4	LOW LINE INPUT. LL_{IN} is the CMOS input to a comparator whose other input is a precision 1.3 volt reference. The output is $\overline{LOW\ LINE}$ and is also connected to the reset pulse generator. See Figure 2.
TEST		1	Used during manufacture only. Always ground this pin.

Typical Applications

MP696

A typical connection for the MP696 is shown in Figure 1. CMOS RAM is powered from V_{OUT}. V_{OUT} is internally connected to V_{CC} when power is present, or to V_{BATT} when V_{CC} is less than the battery voltage. V_{OUT} can supply 50mA from V_{CC}, but if more current is required, an external PNP transistor can be added. When V_{CC} is higher than V_{BATT}, the BATT ON output goes low, providing 7mA of base drive for the external transistor. When V_{CC} is lower than V_{BATT}, an internal 500Ω MOSFET connects the backup battery to V_{OUT}. The quiescent current in the battery backup mode is 1µA maximum when V_{CC} is between 0V and V_{BATT} -700mV.

Reset Output

A voltage detector monitors V_{CC} and generates a $\overline{\text{RESET}}$ output to hold the microprocessor's $\overline{\text{RESET}}$ line low when LL_{IN} is below 1.3V. An internal monostable holds $\overline{\text{RESET}}$ low for 50ms after LL_{IN} rises above 1.3V. This prevents repeated toggling of $\overline{\text{RESET}}$ even if the V_{CC} power drops out and recovers with each power line cycle.

The crystal oscillator normally used to generate the clock for microprocessors take several milliseconds to start. Since most microprocessors need several clock cycles to reset, $\overline{\text{RESET}}$ must be held low until the microprocessor clock oscillator has started. The power-up $\overline{\text{RESET}}$ pulse lasts 50ms to allow for this oscillator start-up time. An inverted, active high, RESET output is also supplied.

Power Fail Detector

The MP696 issues a non-maskable interrupt (NMI) to the microprocessor when a power failure occurs. The power line is monitored via two external resistors connected to the Power Fail Input (PFI). When the voltage at PFI falls below 1.3V, the Power Fail Output ($\overline{\text{PFO}}$) drives the processor's NMI input low. An earlier power fail warning can be generated if the unregulated DC input of the regulator is available for monitoring.

Watchdog Timer

The microprocessor drives the Watchdog Input (WDI) with an I/O line. When OSC IN and OSC SEL are unconnected, the microprocessor must toggle the WDI pin once every 1.6 seconds to verify proper software execution. If a hardware or software failure occurs such that WDI is not toggled, the MP696 will issue a 50ms $\overline{\text{RESET}}$ pulse after 1.6 seconds. This typically restarts the microprocessor's power-up routine. A new $\overline{\text{RESET}}$ pulse is issued every 1.6 seconds until WDI is again strobed.

The Watchdog Output ($\overline{\text{WDO}}$) goes low if the watchdog timer is not serviced within its timeout period. Once $\overline{\text{WDO}}$ goes low, it remains low until a transition occurs at WDI while $\overline{\text{RESET}}$ is high. The watchdog timer feature can be disabled by leaving WDI unconnected. OSC IN and OSC SEL also allow other watchdog timing options, as shown in Table 1 and Figure 7.

MP697

The MP697 is nearly identical to the MP696. The MP697 lacks the battery backup feature, so it does not have the V_{BATT}, V_{OUT}, or BATT ON pins. This allows the MP697 to consume less than 250 microamperes, and it allows the inclusion of RAM write protection pins. See Figure 2.

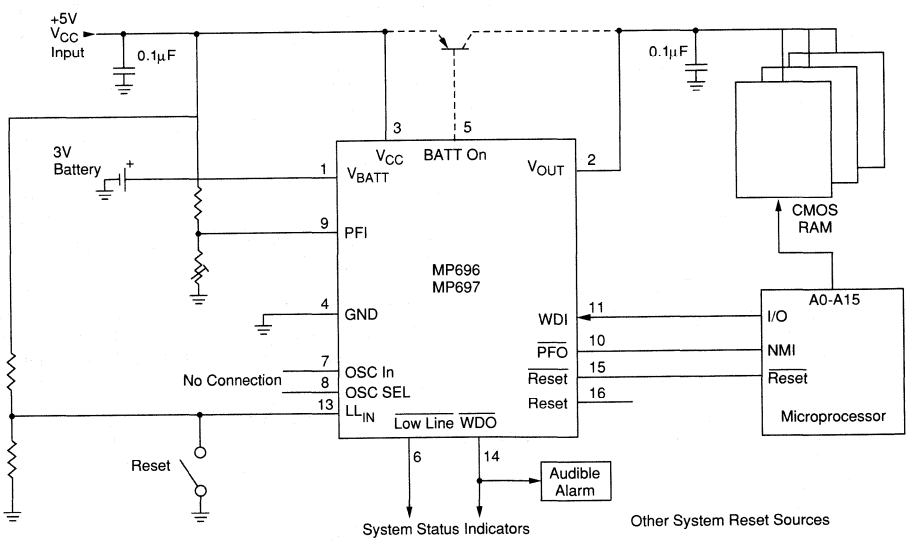
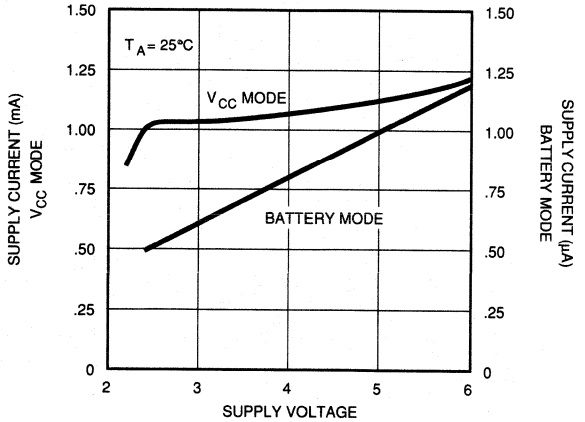


Figure 1. MP696 Typical Application

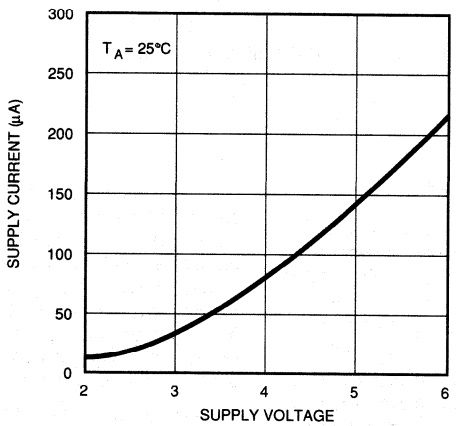
MP696

Supply Current as a Function of Supply Voltage

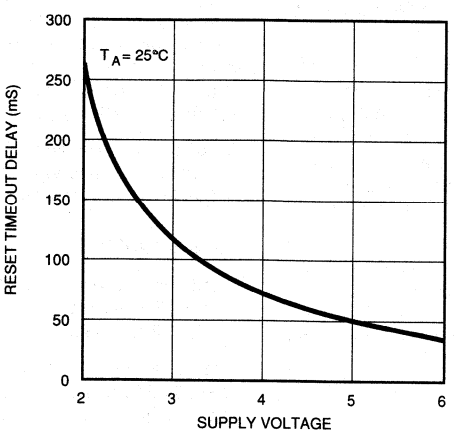


MP697

Supply Current as a Function of Supply Voltage



Reset Timeout Delay as a Function of Supply Voltage



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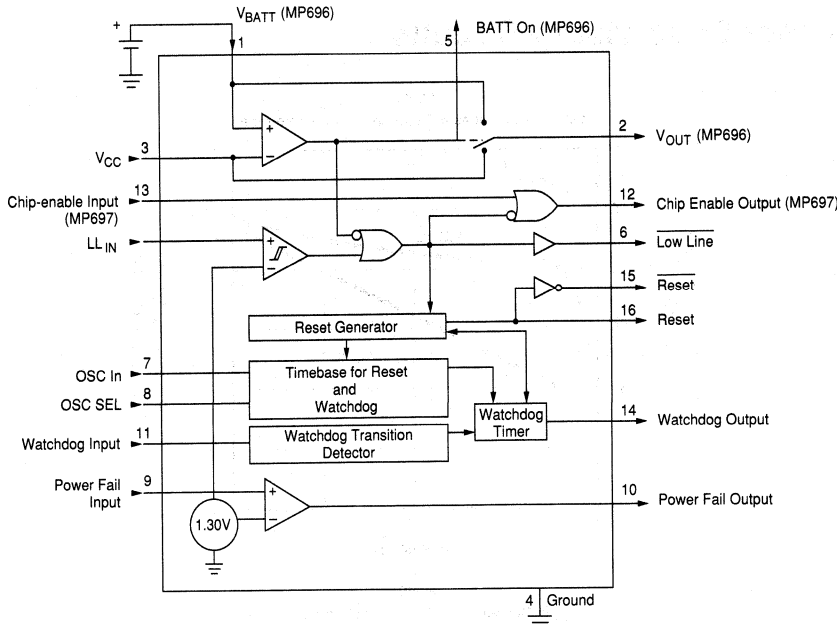


Figure 2. MP696/697 Block Diagram

Detailed Description

Battery-Switchover and V_{OUT} (MP696)

The battery switchover circuit compares V_{CC} to the V_{BATT} input and connects V_{OUT} to whichever is higher. Switchover occurs when V_{CC} is 50mV greater than V_{BATT} as V_{CC} falls and when V_{CC} is 70mV more than V_{BATT} as V_{CC} rises (See Figure 3). The switchover comparator has 20mV of hysterisis to prevent repeated, rapid switching if V_{CC} falls very slowly or remains nearly equal to the battery voltage.

When V_{CC} is higher than V_{BATT}, V_{CC} is internally switched to V_{OUT} via a low saturation PNP transistor. V_{OUT} has 50mA output current capabiltiy and thermal shutdown short circuit protection. Use an external PNP pass transistor in parallel with the internal transistor if the output current requirement at V_{OUT} exceeds 50mA or if a lower V_{CC}-V_{OUT} voltage differential is desired. The BATT ON output can directly drive the base of the external transistor.

It should be noted that the MP696 need only supply the average current drawn by the CMOS RAM if there is adequate filtering. Many RAM data sheets specify a 75nA maximum supply current, but this peak current spike lasts only 100ns. A 0.1µF bypass capacitor at V_{OUT} supplies the high instantaneous current while V_{OUT} need only supply the average load current which is much less. A capacitance of 0.1µF or greater must be connected to the V_{OUT} terminal to ensure stability.

A 500 ohm MOSFET connects the V_{BATT} input to V_{OUT} during battery backup. This MOSFET has very low input-to-output differential (dropout voltage) at the low current levels required for battery backup of CMOS RAM or other low power CMOS circuitry. When V_{CC} equals V_{BATT}, the supply current is typically 12µA. When V_{CC} is between 0V and (V_{BATT} -700mV), the typical supply current is only 600nA typical, 1µA maximum.

The MP696 operates with battery voltages from 2.0V to 4.25V. The battery voltage should not be within 0.5V of V_{CC} or switchover may occur. High value capacitors, either standard electrolytic or the farad-size double layer capacitors, can also be used for short-term memory backup. The capacitor charging voltage should include a diode to limit the fully charged voltage to approximately 0.5V less than V_{CC}. The charging resistor for rechargable batteries should be connected to V_{OUT} since this eliminates the discharge path that exists if the resistor is connected to V_{CC}.

A small leakage current of typically 10nA (20nA max) flows out of the V_{BATT} terminal. This current varies with the amount of current that is drawn from V_{OUT}, but its polarity is such that the backup battery is always slightly charged and is never discharged while V_{CC} is in its operating voltage range. This extends the shelf life of the backup battery by compensating for its self-discharge current. Also note that this current poses no problem when lithium batteries are used for backup since the maximum current (20nA) is safe for even the smallest lithium cells.

If the battery-switchover section is not used, connect V_{BATT} to GND and connect V_{OUT} to V_{CC}. Table 2 shows the status of the input and output in the low power battery backup mode.

Reset Output

$\overline{RESET}$ is an active low output which goes low whenever LL_{IN} falls below 1.3 volts. It will remain low until LL_{IN} rises above 1.312 volts for 50 milliseconds. (See Figures 4 and 5).

The guaranteed minimum and maximum low line thresholds of the MP696/697 are 1.2 and 1.4 volts. The LL_{IN} comparator has approximately 12mV of hysteresis.

The response time of the reset voltage comparator is about 100 microseconds. LL_{IN} should be bypassed to ensure that glitches do not activate RESET output.

$\overline{RESET}$ also goes low if the Watchdog Timer is enabled and WDI remains either high or low longer than the watchdog timeout period. $\overline{RESET}$ hs an internal 3µA pullup and can either connect to an open collector Reset bus or directly drive a CMOS gate without an external pullup resistor.

$\overline{CE}$ Gating and RAM Write Protection

The MP697 uses two pins to control the $\overline{Chip\ Enable}$ or $\overline{Write}$ inputs of CMOS RAMs. When LL_{IN} is > 1.3V, $\overline{CE}$ OUT is a buffered replica of $\overline{CE}$ IN, with a 50ns propagation delay. If LL_{IN} input falls below 1.3V (1.2 min., 1.4 max.), an internal gate forces $\overline{CE}$ OUT high, independent of $\overline{CE}$ IN. The $\overline{CE}$ output is also forced high when V_{CC} is less than V_{BATT}. (See Figure 4.)

CE OUT typically drives the $\overline{CE}$, $\overline{CS}$ or $\overline{Write}$ input of battery backed up CMOS RAM. This ensures the integrity of the data in memory by preventing write operations when V_{CC} is at an invalid level. Similar protection of EEPROMs can be achieved by using the $\overline{CE}$ OUT to drive the $\overline{Store}$ or $\overline{Write}$ inputs of an EEPROM, EAROM, or NOVRAM.

If the 50ns typical propagation delay of $\overline{CE}$ OUT is too long, connect $\overline{CE}$ IN to GND and use the resulting $\overline{CE}$ OUT to control a high speed external logic gate. A second alternative is to AND the $\overline{LOW\ LINE}$ output with the $\overline{CE}$ or $\overline{WR}$ signal. An external logic gate and the $\overline{RESET}$ output of the MP696/697 can also be used for CMOS RAM write protection.

1.25V Comparator and Power Fail Warning

The Power Fail Input (PFI) is compared to an internal 1.3V reference. The Power Fail Output ($\overline{PFO}$) goes low when the voltage at PFI is less than 1.3V. Typically PFI is driven by an external voltage divider which senses either the unregulated DC input to the system's V_{CC} regulator or the regulated output. The voltage divider ratio can be chosen such that the voltage at PFI falls below 1.3V several milliseconds before the LL_{IN} falls below 1.3V. $\overline{PFO}$ is normally used to interrupt the microprocessor so that data can be stored in RAM before LL_{IN} falls below 1.3V and the $\overline{RESET}$ output goes low.

The Power Fail Detector can also monitor the backup battery to warn of a low battery condition. To conserve battery power, the Power Fail Detector comparator is turned off and $\overline{PFO}$ is forced low when V_{CC} is lower than the V_{BATT} input voltage.

Watchdog Timer and Oscillator

The watchdog circuit monitors the activity of the microprocessor. If the microprocessor does not toggle the Watchdog Input (WDI) within the selected timeout period, a 50 milliseconds $\overline{RESET}$ pulse is generated. Since many systems cannot service the watchdog timer immediately after a reset, the MP696/697 has a longer timeout period after a reset is issued. The normal timeout period becomes effective following the first transition of WDI after $\overline{RESET}$ has gone high. The watchdog timer is restarted at the end of Reset, whether the Reset was caused by lack of activity on WDI or by LL_{IN} falling below 1.3V. If WDI remains either high or low, reset pulses will be issued every 1.6 seconds. The watchdog monitor can be deactivated by floating the Watchdog Input(WDI).

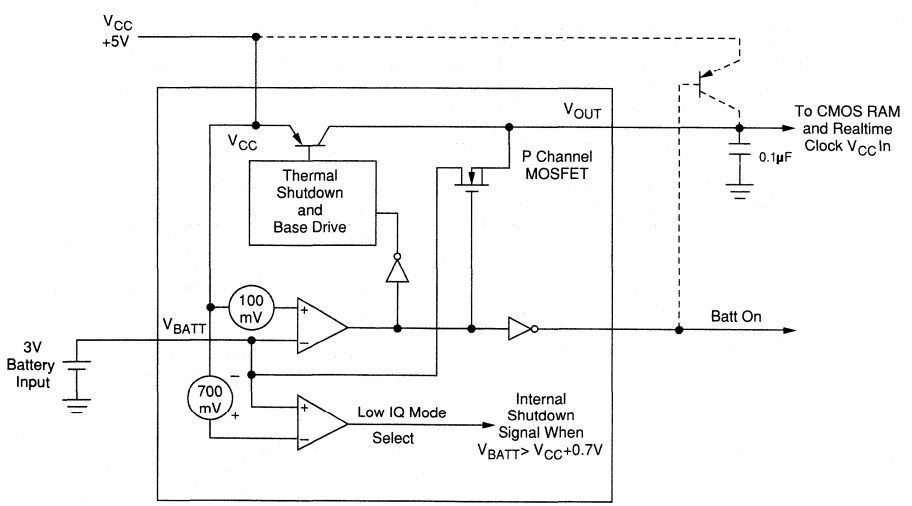


Figure 3. MP696 Battery Switchover Block Diagram

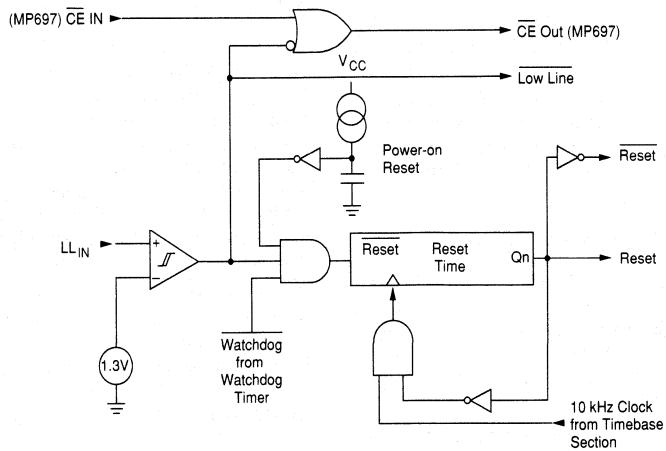


Figure 4. Reset Block Diagram

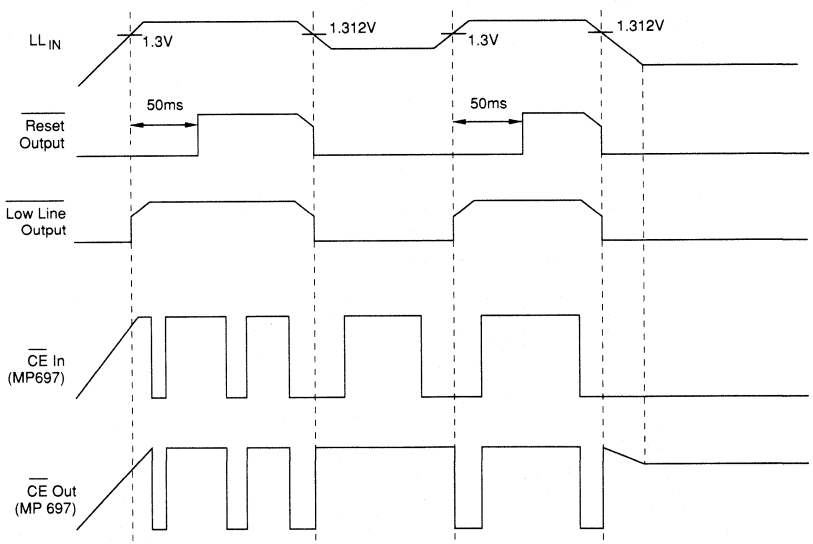


Figure 5. MP697 Reset Timing

The Watchdog Output $\overline{WDO}$ goes low if the watchdog timer "times out," and it remains low until set high by the next transition on the watchdog input. $\overline{WDO}$ is also set high when LL_{IN} goes below 1.3V.

The watchdog timeout period defaults to 1.6 seconds and the reset pulse width defaults to 50ms. The MP696 and MP697 allow these times to be adjusted per Table 1.

The internal oscillator is enabled when OSC SEL is high or floating. In this mode, OSC IN selects between the 1.6 second and 100ms watchdog timeout periods. In either case, immediately after a reset, the timeout period is 1.6 seconds. This gives the microprocessor time to reinitialize the system. WD transmissions while $\overline{RESET}$ is low are ignored. If OSC IN is low, then the 100ms watchdog period becomes effective after the first transition of WDI. The software should be written such that the I/O port driving WDI is left in its power-up reset state until the initialization routines are completed and the microprocessor is able to toggle WDI at the minimum watchdog timeout period of 70ms.

Application Hints

Adding Hysteresis to the Power Fail Comparator

Since the power fail comparator circuit is non-inverting, hysteresis can be added by connecting a resistor between the PFO output and the PFI input as shown in Figure 7. When PFO is low, resistor R3 sinks current from the summing junction at the PFI pin. When PFO is high, the series combination of R3 and R4 source current into the PFI summing junction.

Alternate Watchdog Input Drive Circuits

The Watchdog feature can be enabled and disabled under program control by driving WDI with a 3-state buffer (Figure 8). The drawback to this circuit is that a software fault may erroneously 3-state the buffer, thereby preventing the MP690 from detecting that the microprocessor is no longer working. In most cases, a better method is to extend the watchdog period rather than disabling the watchdog. See Figure 9. When the control input is high, the OSC SEL pin is low and the watchdog timeout is set by the external capacitor. A 0.01µF capacitor sets a watchdog timeout delay of 100 seconds. When the control input is low, the OSC SEL pin is driven high, selecting the internal oscillator. The 100ms or the 1.6 sec. period is chosen, depending on which diode in Figure 9 is used.

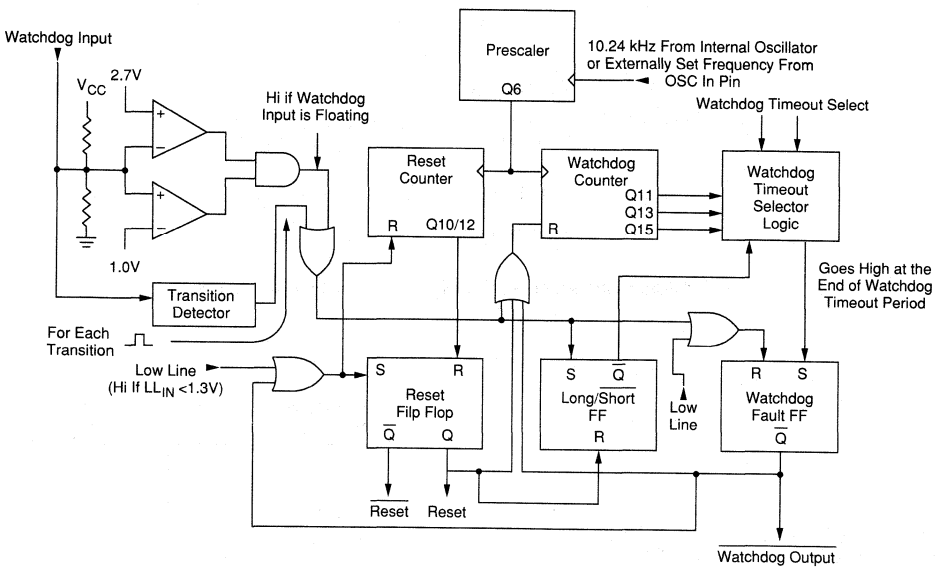


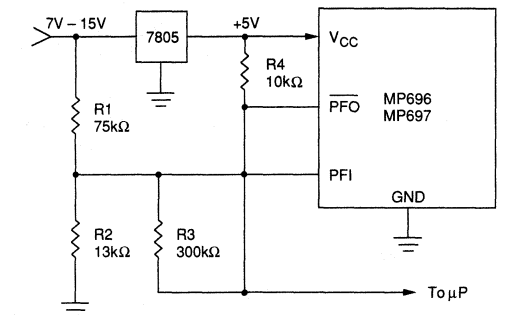
Figure 6. Watchdog Timer Block Diagram

Table 1. MP696 and MP697 Reset Pulse Width and Watchdog Timeout Selections

OSC SEL[3]	OSC IN	Watchdog Timeout Period		Reset Timeout Period
		Normal	Immediately After Reset	
Low	External Clock Input	1024 clks	4096 clks	512 clks
Low	External Capacitor	$\frac{400ms}{47pF} \times C$	$\frac{1.6\ sec}{47pF} \times C$	$\frac{200ms}{47pF} \times C$
High/Floating	Low	100ms	1.6 sec	50ms
High/Floating	High / Floating	1.6 sec	1.6 sec	50ms

Notes:

1. When the MP696/697 OSC SEL pin is low, OSC IN can be driven by an external clock signal, or an external capacitor can be connected between OSC IN and GND.
   The nominal internal oscillator frequency is 10.24kHz.
   The nominal oscillator frequency with external capacitor is $F_{OSC}(Hz) = \frac{184,000}{C_{OSC}(pF)}$
2. See Electrical Specifications Table for minimum and maximum timing values.
3. "HIGH" for the OSC SEL pin should be connected to V_{OUT}, not V_{CC} (on MP696).



$V_H = 9.125V$
$V_L = 7.9V$
Hysteresis = 1.23V

$$V_H = 1.3V \left(1 + \frac{R1}{R2} + \frac{R1}{R3}\right)$$

$$V_H = 1.3V \left(1 + \frac{R1}{R2} + \frac{(5V - 1.3V)\,R1}{1.3V\,(SR3 + R4)}\right)$$

$$\text{Hysteresis} \approx 5V \times \frac{R1}{R3}$$

Assuming R4 $\ll$ R3

Figure 7. Adding Hysteresis to the Power Fail Voltage Comparator

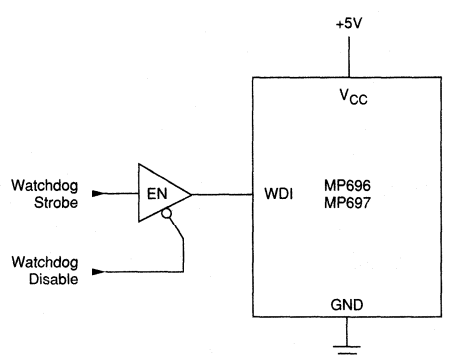


Figure 8. Disabling the Watchdog Under Program Control

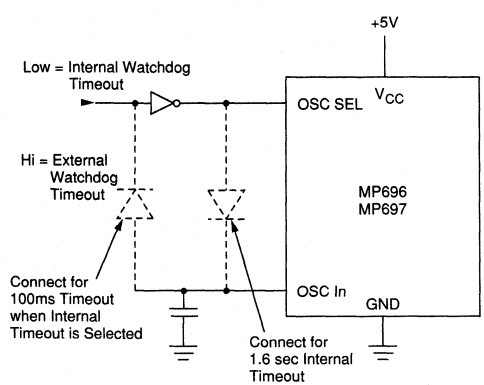


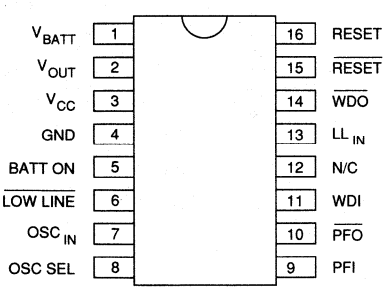
Figure 9. Selecting Internal or External Watchdog Timeout

Table 2. Input and Output Status In Battery Backup Mode

V_{BATT}, V_{OUT}	V_{BATT} is connected to V_{OUT} via internal MOSFET. (MP696 only)
$\overline{RESET}$	Logic low.
RESET	Logic high. The open circuit output voltage is equal to V_{OUT}.
$\overline{LOW\ LINE}$	Logic low.
BATT ON	Logic high. (MP696 only)
WDI	WDI is internally disconnected from its internal pullup and does not source or sink current as long as its input voltage is between GND and V_{OUT}. The input voltage does not affect supply current.
$\overline{WDO}$	Logic high.
PFI	The Power Fail Comparator is turned off and the Power Fail Input voltage has no effect on the Power Fail Output.
$\overline{PFO}$	Logic low.
$\overline{CE}$ IN	$\overline{CE}$ IN is internally disconnected from its internal pullup and does not source or sink current as long as its input voltage is between GND and V_{OUT}. The input voltage does not affect supply current. (MP697 only)
$\overline{CE}$ OUT	Logic high (MP697 only).
OSC IN	OSC IN is ignored.
OSC SEL	OSC SEL is ignored.
V_{CC}	Approximately 12µA is drawn from the V_{BATT} input when V_{CC} is between V_{BATT} + 100mV and V_{BATT} - 700mV. The supply current is 1µA maximum when V_{CC} is less than V_{BATT} - 700mV.

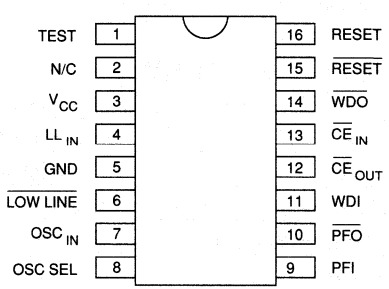
Pin Configuration

MP696



top view

MP697



top view

CMOS Photo-Electric Smoke Detector Integrated Circuit

Ordering Information

Device	Package	Order No.
SD2	16-Pin Plastic	SD2P

Features

- ☐ 6μA – Average Standby Current
- ☐ Minimum Cost of External Components
- ☐ 1mV Sensitivity
- ☐ 8 to 1 Increase of Sample Rate when smoke detected
- ☐ Improved Noise Rejection by multiple sampling
- ☐ Automatic LED Supervisor Alarm
- ☐ Multi-Station Input/Output Capability
- ☐ Horn Modulation Mode Control
- ☐ Piezoelectric Horn Driver
- ☐ Smoke Sensitivity Adjustable by single resistor
- ☐ Self-contained Oscillator requires only a resistor

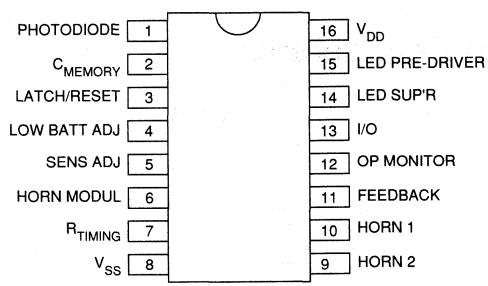
Absolute Maximum Ratings

Supply Voltage	-0.5V to +15.0V
Input Voltage, All inputs	-0.5 to VDD +0.5V
Input Current, Any Input	±10mA
Storage Temperature Range	-40°C to +100°C
Operating Free Air Temperature Range	0°C to +55°C
Power Dissipation (Package)	300mW
Continuous Output Drive Current	25mA
Lead Temperature (Soldering, 10 sec)	300°C
Relative Humidity	90%

General Description

This low power CMOS circuit is intended for use in a pulsed LED/silicon cell smoke detector system. It is designed for use in low power, battery operated, consumer applications with a minimum of external components. This device meets UL217 requirements and is available in a 16-pin plastic DIP.

Pin Configuration



top view

16-pin DIP

Electrical Characteristics

(w/R-(7) = 22 Meg Ω then f_{OSC} = 485 Hz; T_A = 25° C;V_{DD} = 9V, unless otherwise specified)

Symbol	Parameter	Min	Typ	Max	Units	Conditions
I_{IN}	Photodiode Input Leakage Current		0.01	±1.0	nA	
ν_{PD}	Photodiode Input Signal Sensitivity	0.5	0.8	1.1	mV	C_{mem} = .05μF C_{input} = 5pF τ_{LED} = 100μ sec
V_{BTH}	Low Battery Threshold Voltage	7.3	7.7	8.2	V	R(4) = ∞
	Horn Modulation Frequency		8		Hz	PIN 6 to V_{DD} R(7) = 22 meg Ω Smoke Detected
	Horn Modulation Duty Cycle		62.5		%	
τ_{TBL}	Low Battery/LED Supervisor Trouble Alarm Pulse Width		17		mSec	@ f_{OSC} = 485 Hz R(7) = 22 Meg Ω
T_{TBL}	Low Battery/LED Supervisor Alarm Period		35		sec	@ f_{OSC} = 485 Hz R(7) = 22 Meg Ω
I_{OUT}	Horn Output Current	± 25			mA	V_O = IV Sink V_O = 8V Source
V_{IN}	Feedback Input Voltage Range	V_{SS} - 15		V_{DD} + 15	V	Typical Min and Max. Not 100% tested
I_{OM}	Operation Monitor Output Current, Source	-2.5	-4.5		mA	V_{OM} = 2.0V
$I_{I/O}$	I/O Output Source Current	-4.0	-10.0		mA	$V_{I/O}$ = V_{DD} -1.0
$V_{I/O}$	Remote Alarm Trigger Voltage	0.6 V_{DD}			V	Sink Current 20mA typical at V_{DD} = 4.5V
V_{IH-ON}	LED Supervisor, upper Threshold Range	V_{DD} - 0.8		V_{DD} - 0.2	V	
V_{I-OFF}	LED Supervisor, Safe Region	V_{DD} - 2.5		V_{DD} - 0.8		
V_{IL-ON}	LED Supervisor, lower Threshold Range	V_{DD} - 4.0		V_{DD} - 2.5		
I_{LED}	LED Output Source Current	-10	-20		mA	V_{LED} = 5V
T_{LED}	Photodiode Sample Pulse Period (Smoke Detected)		1.0		sec	f_{OSC} = 485 Hz
T_{LED}	Photodiode Sample Pulse Period (Smoke Detected)		8.0		sec	f_{OSC} = 485 Hz R(7) = 22 meg Ω
V_{DD}	Supply Voltage	7.0	9.0	10.0	V	
I_{DD}	Average Standby Supply Current		6.0	10.0	μA	R(7) = 22 Meg Ω V_{DD} = 9.0, Non-Alarm Mode

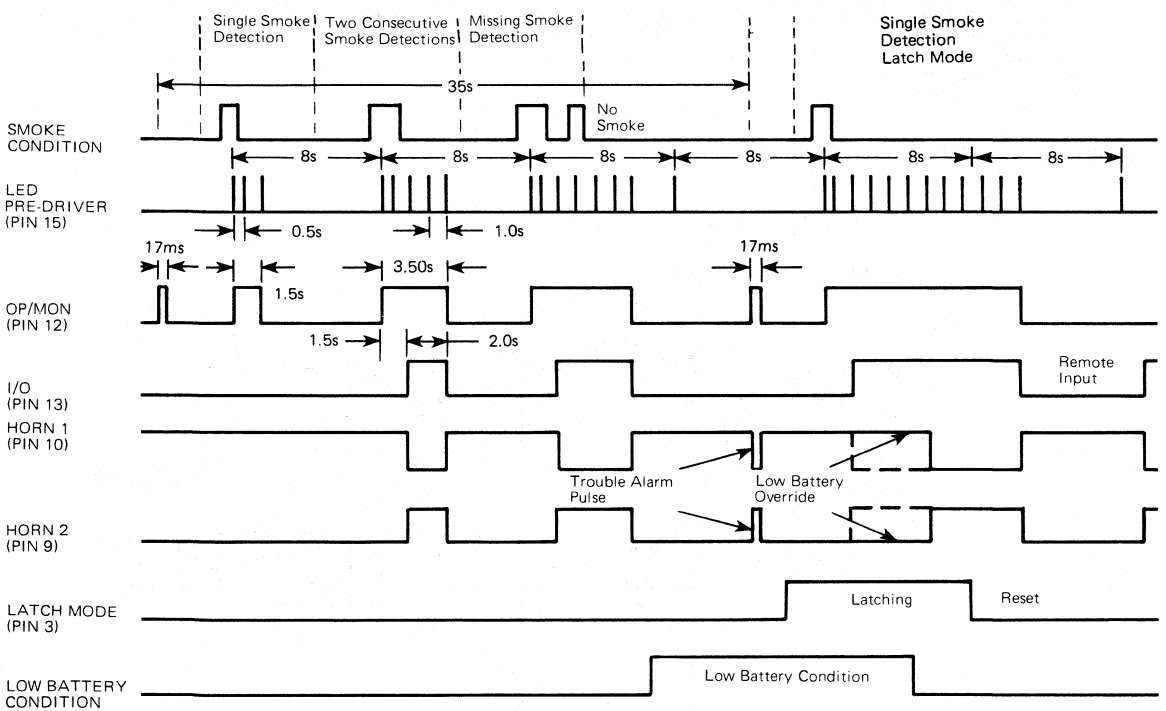
Pin Definition

Pin	Name	Function
1	Photodiode Input	Connect the cathode of a VTS-4085S, or equivalent, to pin 1. Connect the anode to V_{DD}. The typical allowed signal range is from V_{DD} to V_{DD} - 1.0V.
2	Memory Capacitor Input	The capacitor may range from 0.01µF to 0.05µF and should have low leakage. The detector sensitivity increases with increasing capacitance.
3	Latch/Reset Input	When connected to V_{DD}, the detector will latch on at the first detection of smoke. When connected to V_{SS}, the alarm will not latch on detection of smoke and the low battery condition will not override the smoke alarm condition. Reset after latching is accomplished by momen tarily connecting this pin to V_{SS} until the horn silences. The Latch/Reset Input only affects the local smoke alarm response.
4	Low Battery Threshold	The nominal threshold of the battery alarm is 7.7 volts. The alarm point can be raised by connecting an adjustment resistor to ground, and lowered by connecting a resistor to V_{DD}.
5	Smoke Sensitivity Adjustment	A resistor or potentiometer to ground is used to adjust the duration of the LED pulse and thereby the Smoke Sensitivity. Pulse duration is proportional to the resistor value and varies approximately 100µsec per megohm.
6	Horn Modulation Control Input	When connected to V_{DD}, the Horn will pulse ON and OFF at approximately 8 Hz, with the ON time exceeding the OFF time. When connected to V_{SS}, the "Smoke" alarm will sound the Horn continuously. This control only affects the "Smoke" alarm condition.
7	Timing Resistor	A nominal resistor value of 22 megohms to V_{SS} sets the oscillator frequency to 485 Hz. Thus: a) The IR LED pulses every 8 seconds in standby. b) The OPERATION MONITOR LED pulses every 35 seconds in standby. c) The Horn modulation (ON-OFF) frequency is approximately 8Hz. d) The Low Battery or LED SUPERVISOR trouble pulse to the Horn will occur every 35 seconds, with 17ms duration. e) The IR LED will pulse every 1 second when smoke is detected. f) The Horn will be silenced just before each IR LED pulse for 4.2 ms, to reduce electro-magnetic interference.
8	V_{SS}	Connect this pin to circuit common, the lowest potential.
9	Horn Output 2	This terminal is connected to the brass electrode of the piezoelectric horn.
10	Horn Output 1	This pin is connected to the large silver electrode of the piezoelectric horn.
11	Horn Feedback	This pin is connected to the small silver electrode of the piezoelectric horn.
12	Operation Monitor	This output is a current source of 4mA for driving a visible LED. The LED will flash for 17ms every 35 seconds under normal conditions. The LED will be ON continuously when smoke is first detected. This occurs before the alarm sounds and indicates that the detector is in speed-up mode (1.0 second LED pulse period). This output indicates which unit is alarming in multiple station applications. When this output is used for both local LED indication and remote logic, a resistor must be placed in series with the LED.
13	Multiple Station Input/Output	This Input/Output may be connected via twisted pairs to at least 20 other units. The output goes high after at least two consecutive smoke detections have been made. The output structure allows units of different operating voltages to be connected together with no impairment of performance or excessive loading of the higher voltage units. There is an active pull-down on the output. Because of the high current-sourcing capability of the output, this pin should never be connected to V_{SS} via a low impedance path. An Input level of greater than $0.6V_{DD}$ volts is required to ensure a local alarm.
14	LED Supervisor	This pin must be connected to the LED circuit as shown. Failures detected are open or shorted conditions in the LED and Driver circuit. A failure is indicated by a local pulsed trouble alarm. To defeat this feature, pin 14 must be tied to a voltage about 1.5-volts below V_{DD}, or to pin 2 in most applications.
15	LED Pre-Driver Output	This terminal can source about 13mA. The output voltage is zener clamped at approximately 6.7V and the current becomes limited. The LED current set resistor may be put in the collector circuit, below the LED, but the LED current and therefore the Sensitivity of the smoke detector will vary with supply voltage.

Pin Definition (cont.)

Pin	Name	Function
16	V_{DD}	This pin is connected to the positive battery terminal. Pin 16 should be solidly connected to the V_{DD} side of both the photodiode and the memory capacitor. A V_{DD} guard-ring type foil path around pins 1 and 2 will enhance noise immunity of the detection circuit. This circuit will operate from 7 to 10 volts, although average standby current will increase with supply voltage. Protect the integrated circuit from polarity reversal.
9,10	Alternate Driver for Electro-Mechanical Horns	When the smoke detector circuit is used to drive either a transistorized mechanical or electro-mechanical horn, the feedback (pin 11) must be connected to V_{DD}. When an alarm condition is not present, pin 10 will be at V_{DD} and pin 9 will be at V_{SS}. When an alarm condition is present, pin 10 will switch from V_{DD} to V_{SS} and pin 9 will switch from V_{SS} to V_{DD}. Both horn outputs are capable of sinking or sourcing more than 100mA at a 9-volt supply voltage. The steady state on current is limited to 25mA. Pin 9 must not remain at V_{DD} when chip is reset.
	Transistorized Mech. Horn	The control tab of the horn is connected to pin 9 and pin 10 is left open.
	Electro-Mechanical Horn	Pin 9 is connected through a resistor to the base of an NPN horn driver transistor. Pin 10 is left open.

Timing Waveform



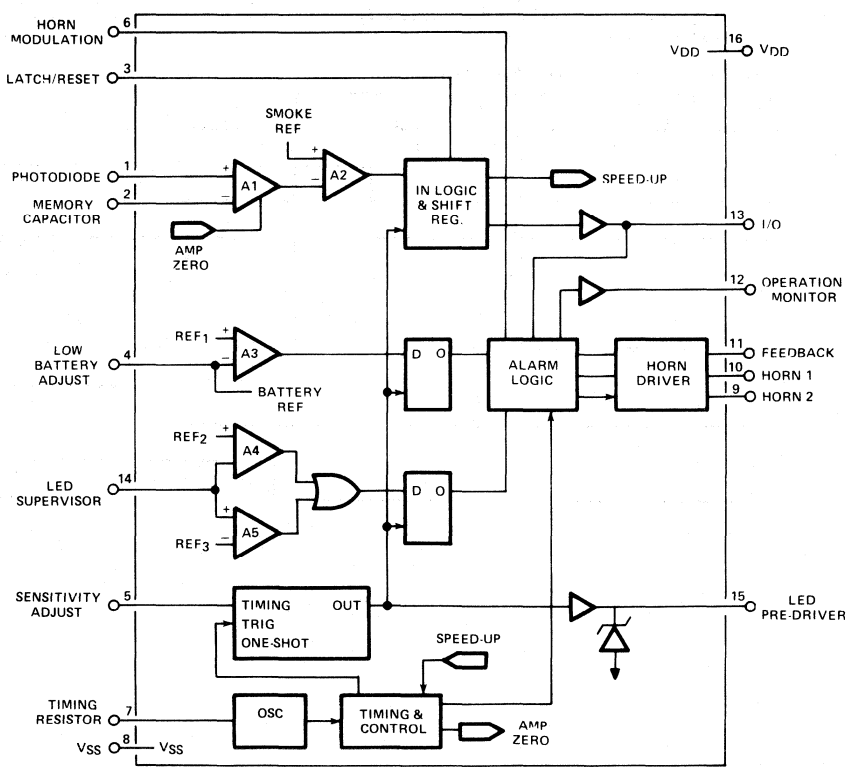
Truth Table

Alarm Status	Input Conditions								Output Conditions				
	Smoke	Low Batt.	LED Sup'r	Pin 3 Latch	Pin 4 Batt	Pin 6 Mod'l	Pin 11 Fdbk	Pin 13 I/O	Pin 9 H2	Pin 10 H1	Pin 12 OP/MO	Pin 13 I/O	Pin 15 LED
Standby	F	F	F	X	N	X	H[4]	N	L	H	P[1]	L	P[2]
Remote	F	X	X	X	N	L	H[4]	H	H[5]	L[5]	P[1]	N	P[2]
Smoke	F	X	X	X	N	H	H[4]	H	H[5,6]	L[5,6]	P[1]	N	P[2]
Local	T (A)	X	X	L	N	L	H[4]	N	H[5]	L[5]	H	H	P[3]
Smoke	T (A)	X	X	L	N	H	H[4]	N	H[5,6]	L[5,6]	H	H	P[3]
Local	T (B)	F	X	H	N	L	H[4]	N	H[5]	L[5]	H	H	P[3]
Smoke	T (B)	F	X	H	N	H	H[4]	N	H[5,6]	L[5,6]	H	H	P[3]
Latched	T (B)	T	X	H	N	X	H[4]	N	L[1]	H[1]	H	H	P[3]
Low Batt	F	T	X	X	N	X	H[4]	N	L[1]	H[1]	P[1]	L	P[2]
LED Sup'r	F	X	T	X	N	X	H[4]	N	L[1]	H[1]	P[1]	L	P[2]
Batt Disable	F	T	F	X	H	X	H[4]	N	L	H	P[1]	L	P[2]
Horn Disable	X	X	X	X	N	X	L	N	L	H	X	X	X

Key:
- T – Logical TRUE, Analog Condition
- F – Logical FALSE, Analog Condition
- H – Logical HIGH, Digital Level or Driver Sourcing
- L – Logical LOW, Digital Level or Driver Sinking
- P – Output PULSE HIGH, Normally LOW
- N – No Signal Applied / Open
- X – Unspecified
- A – After two consecutive smoke detections
- B – After one smoke detection

Notes:
1. Pulsed to opposite state ONCE every fourth PULSE on pin 15.
2. Normal Sample Rate, Typical 8 seconds.
3. 8 Times Normal Sample Rate, Typical 1.0 second.
4. When used with a piezo horn, this signal is oscillating,but considered HIGH.
5. When used with a piezo horn, this signal is oscillating.
6. Signal will be in non-alarm state 37.5% of time.

Block Diagram



Operation

This device utilizes low power CMOS technology to provide all of the necessary functions of a battery operated, photoelectric smoke detector using a minimum of external components.

The LED PRE-DRIVER output pulses an external transistor which in turn, switches on the infrared light emitting diode at a very low duty cycle. The desired IR LED pulse period is determined by the value of the external timing resistor. The Smoke Sensitivity is adjustable through a trimmer resistor which varies the IR LED pulse width.

The light sensing element is a silicon photovoltaic cell which is held at near zero bias to minimize leakage currents. The circuit can detect signals as low as 1mV and generate an alarm. The IR LED pulse repetition rate increases when smoke is detected.

For use with a 9-volt battery, an internal zener is incorporated into the IC. When the minimum battery voltage is reached (tested during the IR LED on pulse), the output produces a short trouble alarm pulse or "blip". The horn is pulsed after every fourth IR LED pulse. When the alarm mode control is set for non-latching operation, the unit will sound a continuous alarm when smoke is detected even during low battery conditions. When the alarm mode control is set for latching operation, the low battery trouble alarm will override the smoke alarm, in accordance with UL217specifications.

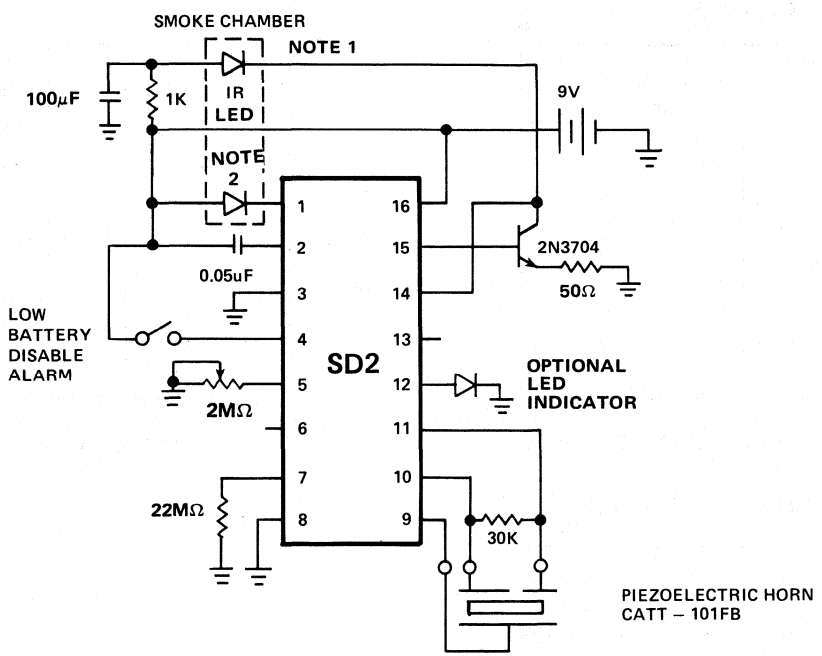
The LED SUPERVISOR tests for open or shorted conditions in the LED and Driver circuit. For either condition of the IR LED when pulsed, failure of the forward voltage to fall between two limits produces a trouble alarm pulse on the Horn after every fourth LED pulse.

The Input/Output terminal (I/O) is used to interconnect SD2 units for multiple station applications.

The OPERATION MONITOR pulses a visible LED after every fourth IR LED pulse to indicate device operation. For a local smoke detection the LED is driven continuously.

The Horn Driver circuit self-oscillates with a piezoelectric element or enables an electro-mechanical horn when pin 11 is connected to V_{DD}.

Typical System — Non-Latching Single Station

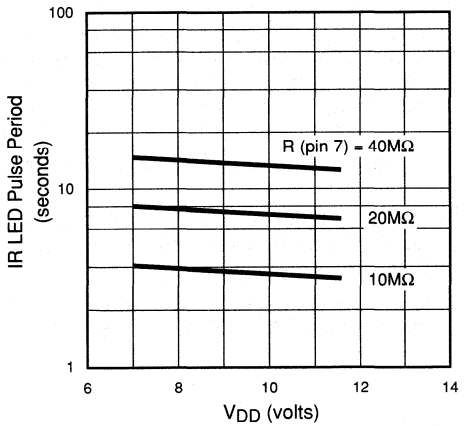


Notes: 1. **IR Diode RCA Type SG 1010A or Spectronics Type SE 5455-4 Clairex Type CLED-1**

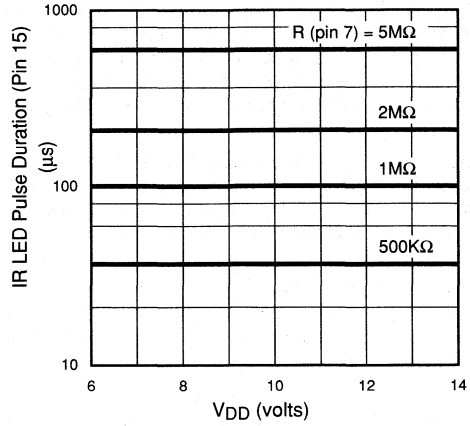
2. **IR Photo detectors Vactec VTS4085**

Typical Performance Curves (T_A = 25°C unless otherwise noted)

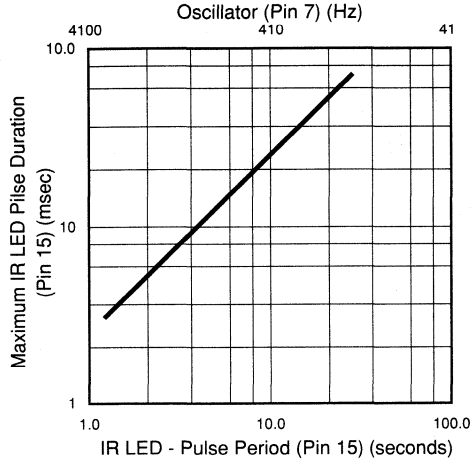
T_{LED} vs V_{DD}



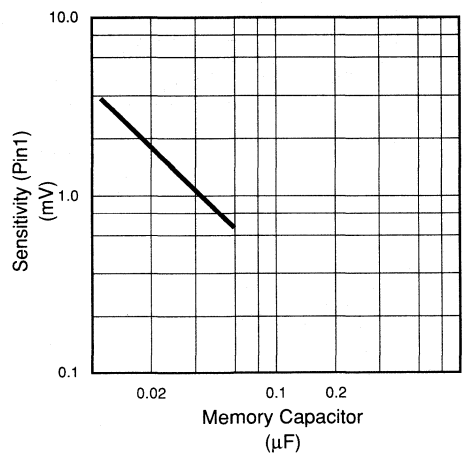
T_{PD} vs V_{DD}



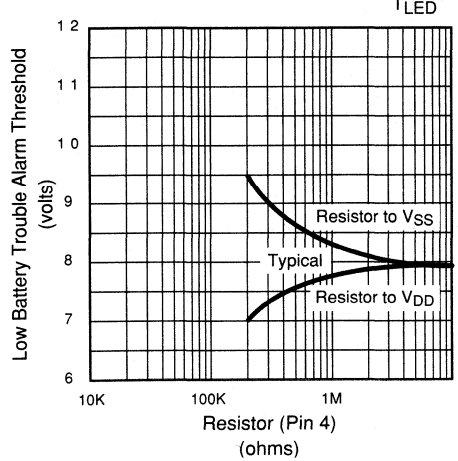
IR LED vs T_{LED} vs Oscillator Oscillator (Pin 7) (Hz)



Detector Sensitivity vs C_{MEM}



$$I_{AVG}(LED) = [(I_{OH}(15)) + I_{LED}] \frac{T_{PD}}{T_{LED}}$$

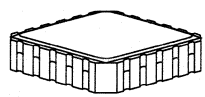


Surface Mount Packages

Various surface mount packages are available for HVCMOS, DMOS, and CMOS devices. Refer to the respective product data sheet for availability and package outline for detailed dimensional drawings. This section also includes lead bend and taping options.

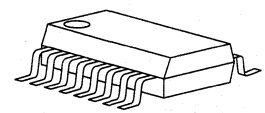
SOT-89

N8



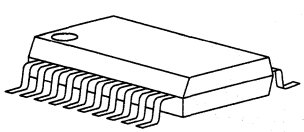
Type "C" Leadless
20 Terminal
Ceramic Chip Carrier

NF



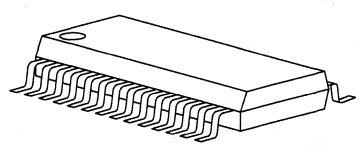
16-Lead
Small Outline

AG



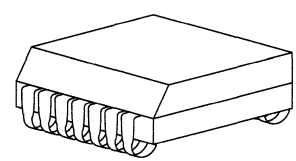
20-Lead *
Small Outline

WG



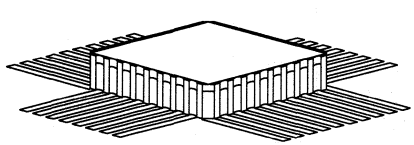
28-Lead *
Small Outline

WG



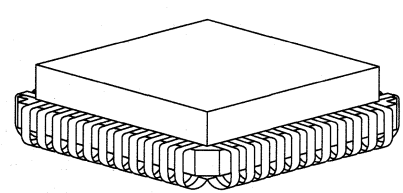
28-Lead Plastic Quad
"J" Bend

PJ



36-Leaded Ceramic Chip Carrier

CS

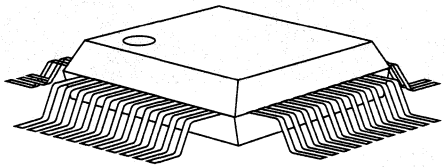


44-Lead Plastic and Ceramic Quads
"J" Bend

PJ / DJ

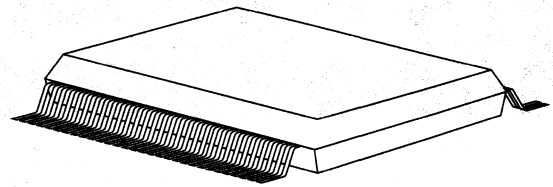
13

* 300 mil wide body



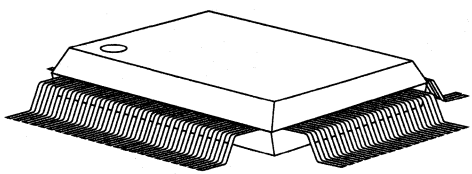
44-Lead Plastic Gullwing

PG



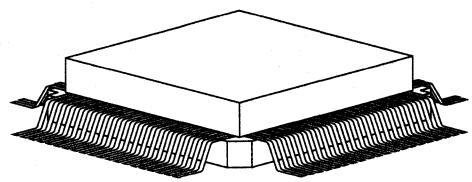
60-Lead 2-Sided Plastic Gullwing

PG



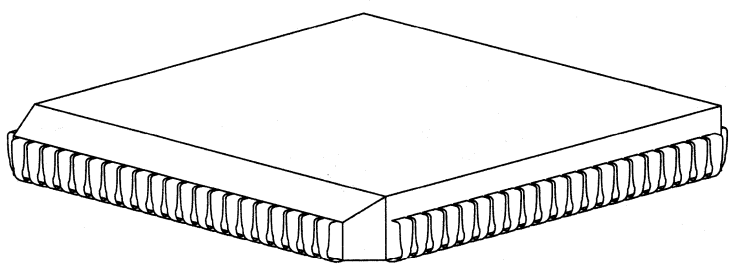
64-Lead 3-Sided Plastic and Ceramic Gullwing

PG / DG



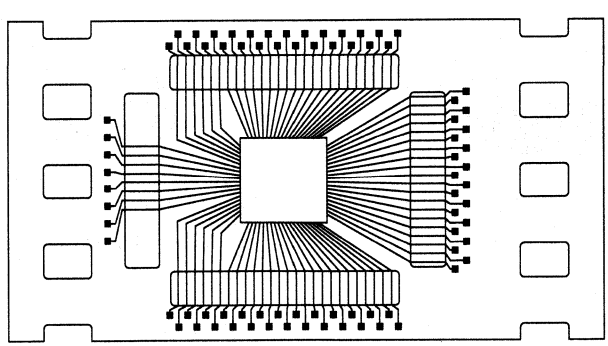
80-Lead Plastic and Ceramic Gullwing

PG / DG



84-Lead Plastic "J" Bend

PJ



Die on Tape
(for Tape Automated Bonding)

T

Lead Bend Options

Lead bend options are available in order to retrofit existing boards with small, cost effective, pin-compatible TO-92 packages, or for the purpose of surface mounting.

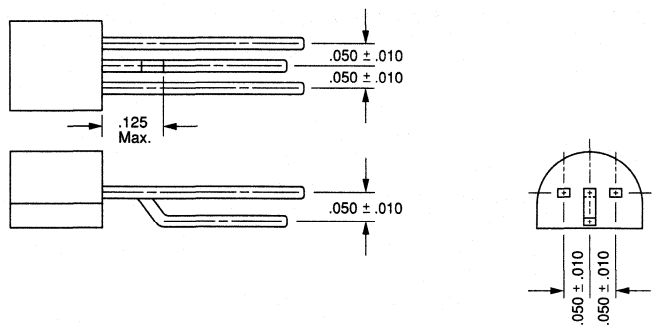


Figure 1
TO-92 leads bent for TO-18 or TO-52 pin circle (Ordering information: Option P015)*

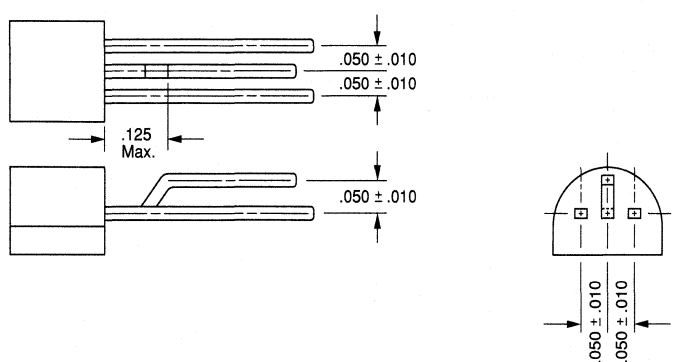


Figure 2
TO-92 leads bent for reversed TO-18 or TO-52 pin circle (Ordering information: Option P016)*

13

*Lead lenghts are those of original components as shown in the Package Outline Section (i.e., uncropped, unless otherwise specified).

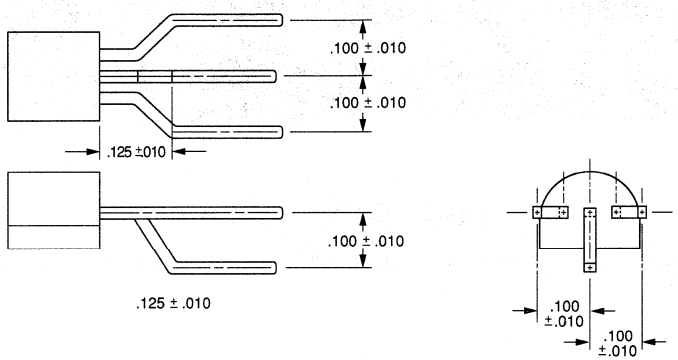


Figure 3
TO-92 leads bent for TO-5 or TO-39 pin circle (Ordering information: Option P017)*

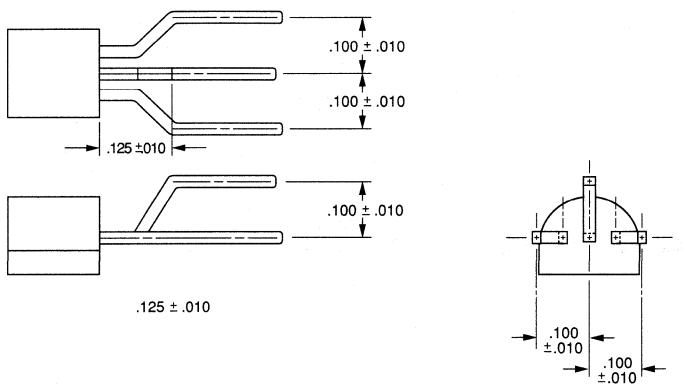


Figure 4
TO-92 leads bent for reversed TO-5 or TO-39 pin circle (Ordering information: Option P018)*

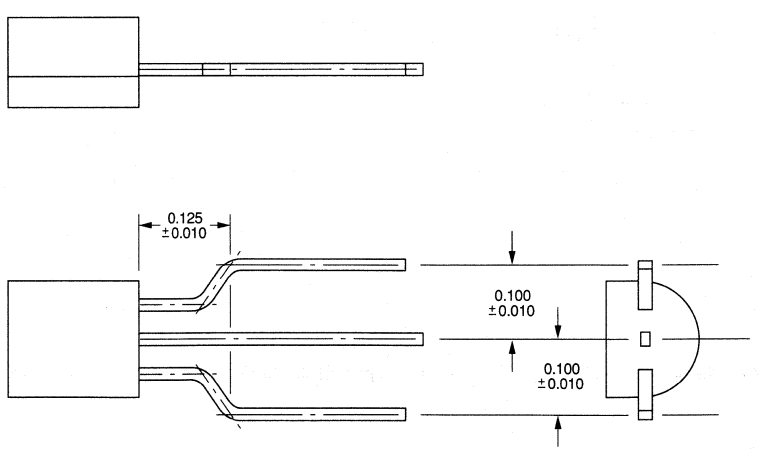


Figure 5
TO-92 leads bent for TO-220 (Ordering information: Option P011)*

*Lead lenghts are those of original components as shown in the Package Outline Section (i.e., uncropped, unless otherwise specified).

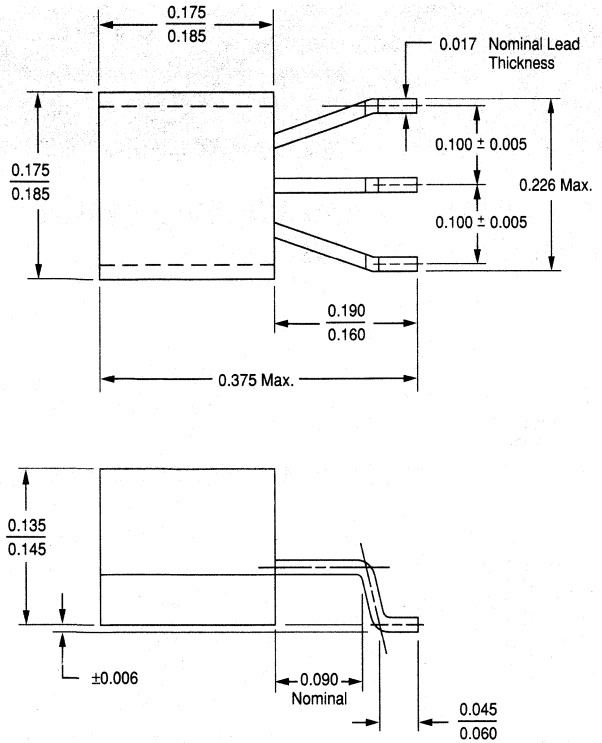


Figure 6
TO-92 for surface mounting. Leads formed for pad spacing of 0.100" center to center. (Ordering information: Option P010)

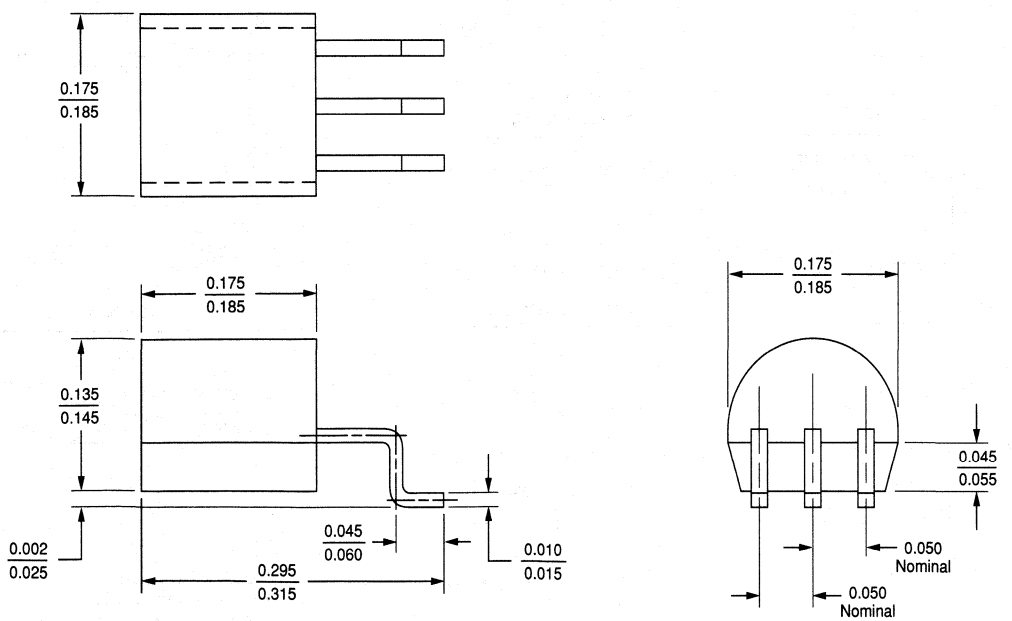
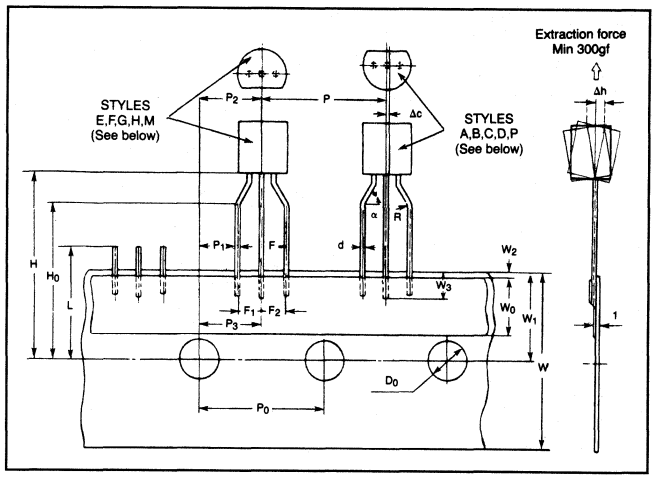


Figure 7
TO-92 for surface mounting. Leads formed for pad spacing of 0.050" center to center. (Ordering information: Option P012)

Supertex inc.

TO-92 Taping Specifications and Winding Styles (per EIA Standard RS468)

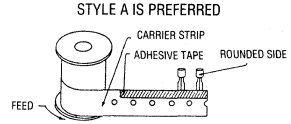


P	12.7 ± 0.5	H_0	16 ± 0.5
P_0	12.7 ± 0.2	F	$5^{+0.8}_{-0.2}$
P_1	3.85 ± 0.5	$F_1 - F_2$	± 0.3
P_2	6.35 ± 0.5	D_0	4 ± 0.2
P_3	6.35	t	0.7 ± 0.2
W	$18^{+1.0}_{-0.5}$	Δ_h	0 ± 1
W_0	6 ± 1	d	$0.50^{+0.06}_{-0.05}$ dia.
W_1	9 ± 0.5	R	0.8
W_2	Max. 0.5	α	45° – 60°
W_3	Min. 4.5	L	Max. 11
H	19.5 ± 0.5	Δ_C	0 ± 0.5

All dimensions in millimeters.

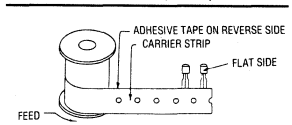
STYLE A (P003)

STYLE A IS PREFERRED



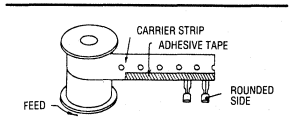
ROUNDED SIDE OF TRANSISTOR AND ADHESIVE TAPE VISIBLE

STYLE B (P004)



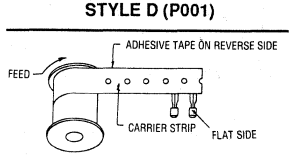
FLAT SIDE OF TRANSISTOR AND CARRIER STRIP VISIBLE
(ADHESIVE TAPE ON REVERSE SIDE)

STYLE C (P005)



ROUNDED SIDE OF TRANSISTOR AND ADHESIVE TAPE VISIBLE

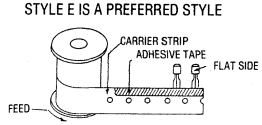
STYLE D (P001)



FLAT SIDE OF TRANSISTOR AND CARRIER STRIP VISIBLE
(ADHESIVE TAPE ON REVERSE SIDE)

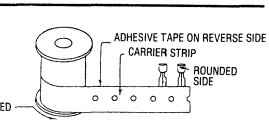
STYLE E (P002)

STYLE E IS A PREFERRED STYLE



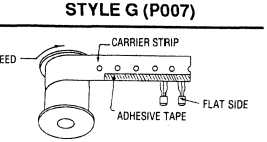
FLAT SIDE OF TRANSISTOR AND ADHESIVE TAPE VISIBLE

STYLE F (P006)



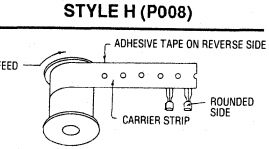
ROUNDED SIDE OF TRANSISTOR AND CARRIER STRIP VISIBLE
(ADHESIVE TAPE ON REVERSE SIDE)

STYLE G (P007)



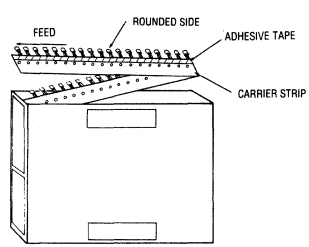
FLAT SIDE OF TRANSISTOR AND ADHESIVE TAPE VISIBLE

STYLE H (P008)



ROUNDED SIDE OF TRANSISTOR AND CARRIER STRIP VISIBLE
(ADHESIVE TAPE ON REVERSE SIDE)

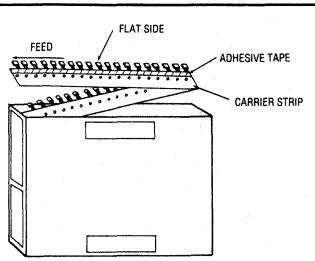
STYLE P (P013)



ROUNDED SIDE OF TRANSISTOR AND ADHESIVE TAPE VISIBLE

STYLE P IS EQUIVALENT TO STYLES A, B, C, D OF REEL PACK DEPENDING ON WHICH BOX-FLAP IS OPENED AND WHICH END OF THE BOX THE DEVICES ARE FED FROM.

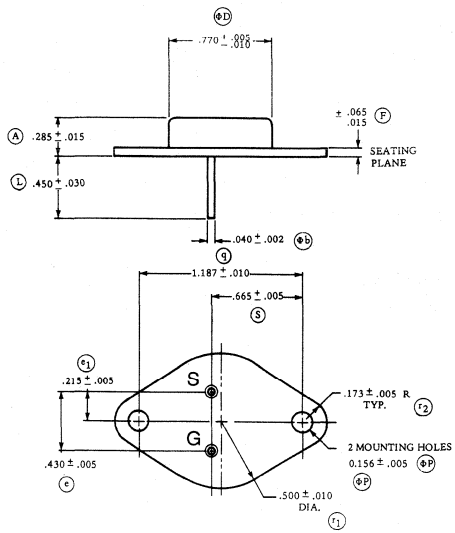
STYLE M (P014)



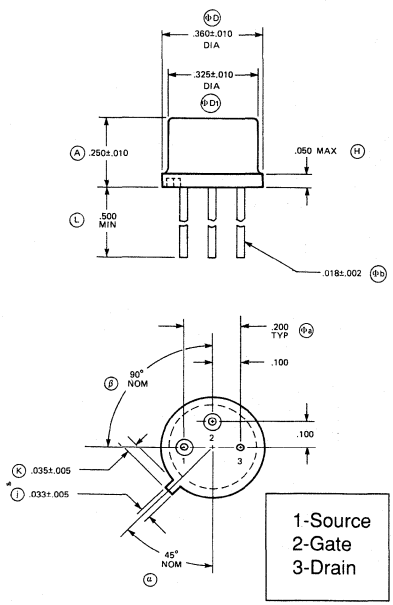
FLAT SIDE OF TRANSISTOR AND ADHESIVE TAPE VISIBLE

STYLE M AMMO PACK IS EQUIVALENT TO STYLES E, F, G, H OF REEL PACK DEPENDING ON WHICH BOX-FLAP IS OPENED AND WHICH END OF THE BOX THE DEVICES ARE FED FROM.

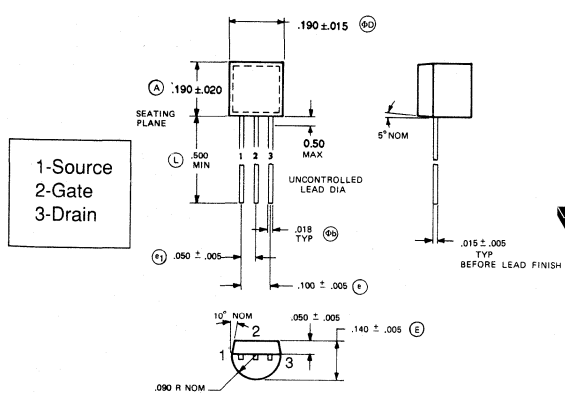
Package Outlines



TO-3 Metal Can Packages
2-Lead (Steel)

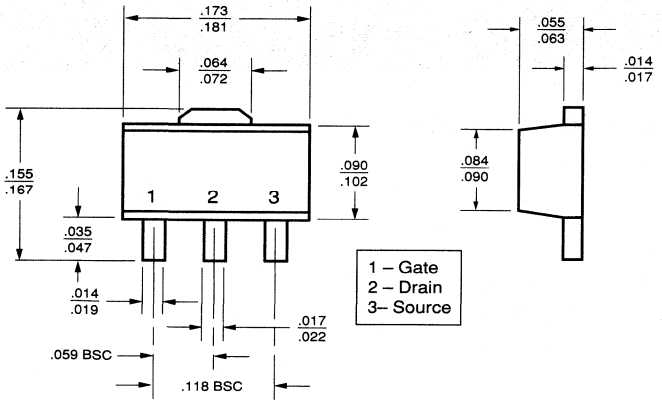


TO-39 Metal Can Package
3-Lead

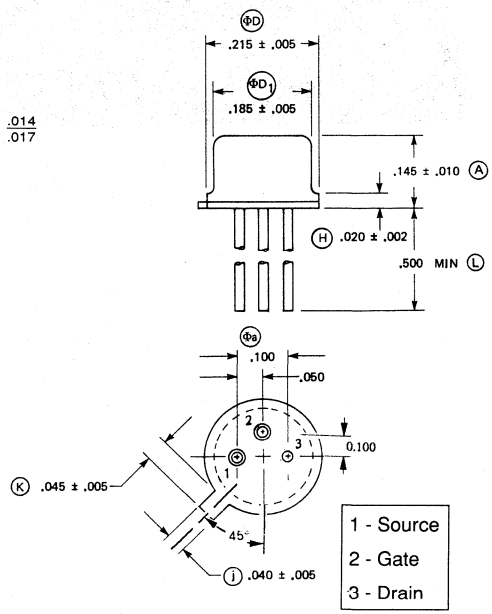


TO-92 Plastic Package
3-Lead

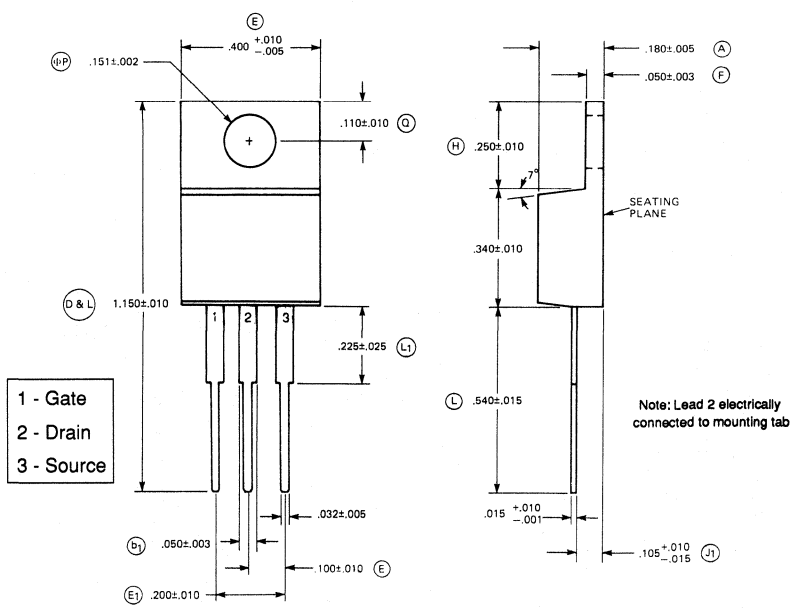
Note: Circle (e.g., (B)) indicates JEDEC Reference.



TO-243AA (SOT89)
Surface Mount

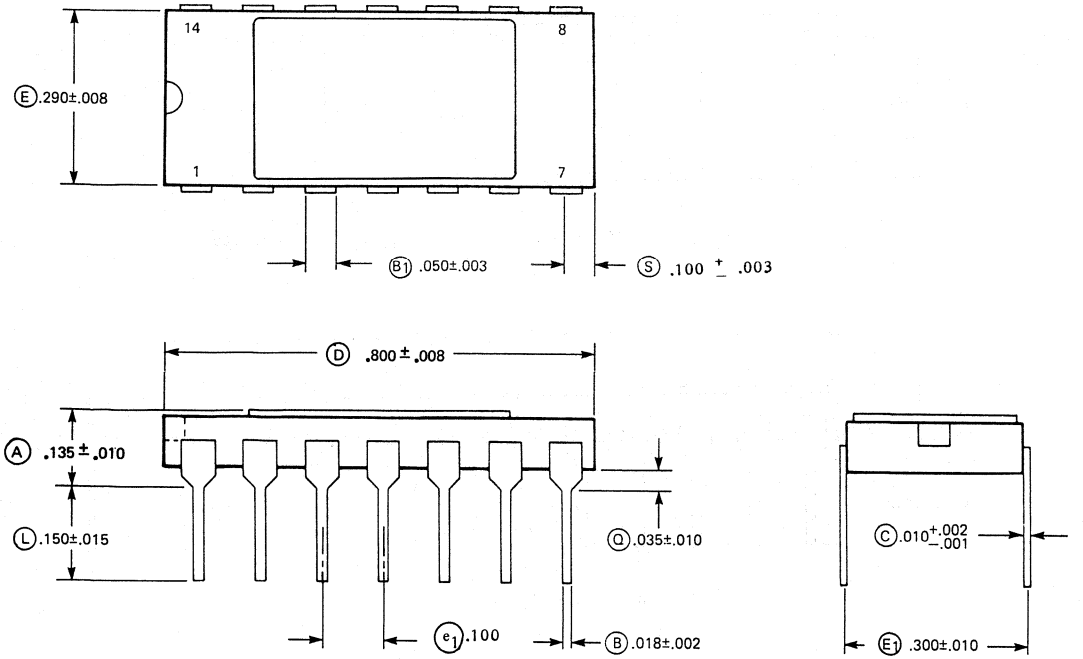


TO-52 Metal Can Package
3-Lead

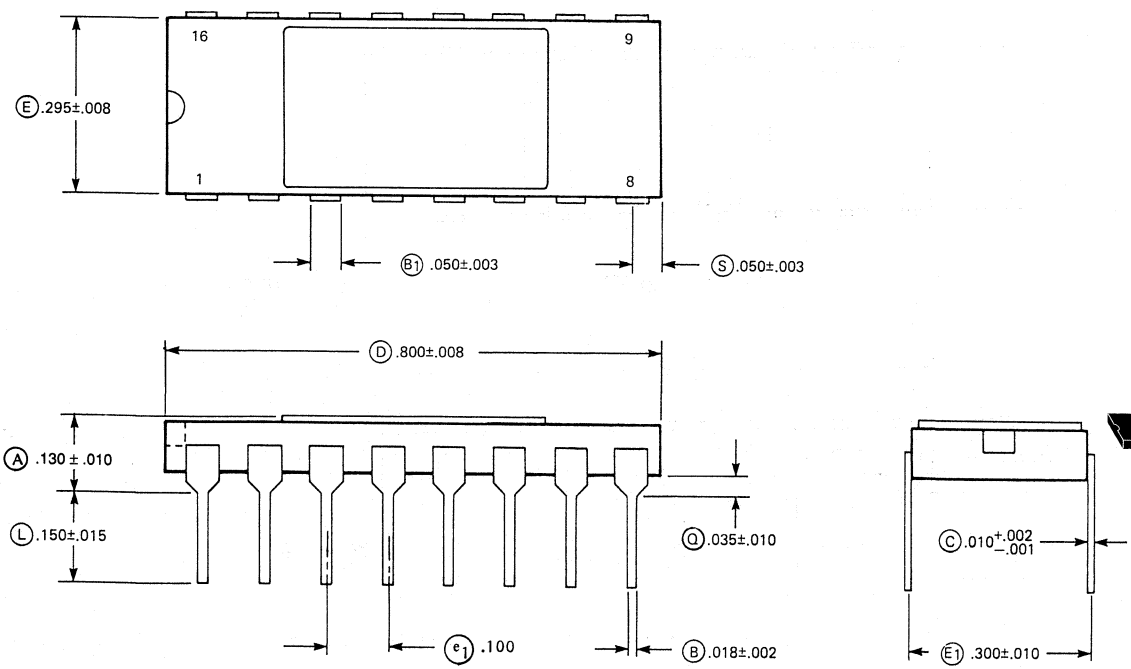


TO-220 Power Package
3-Lead

Note: Circle (e.g., (B)) indicates JEDEC Reference.

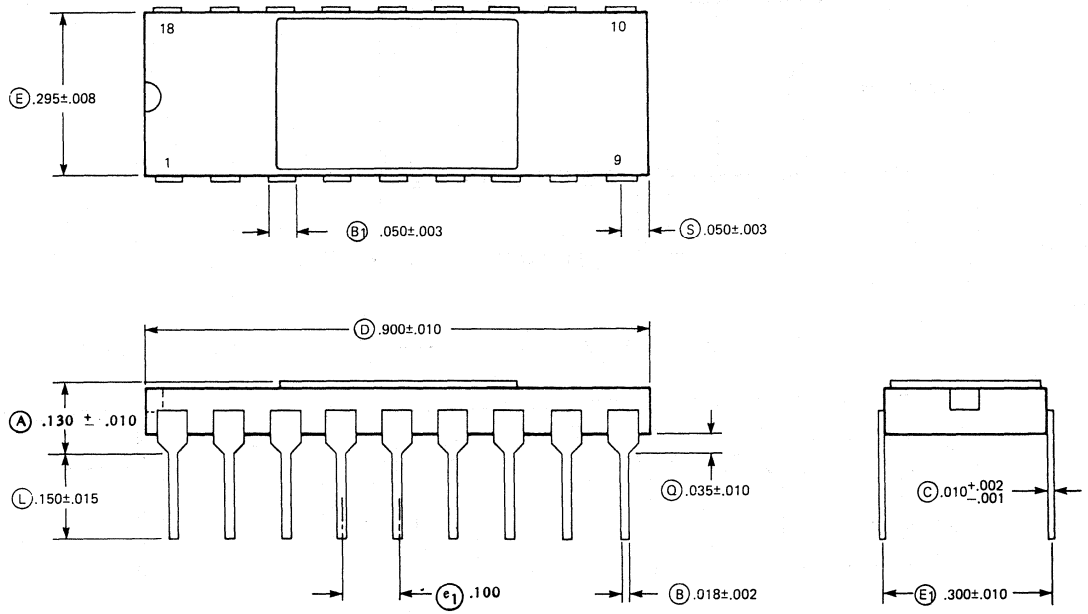


14-Lead Ceramic Side Brazed Package

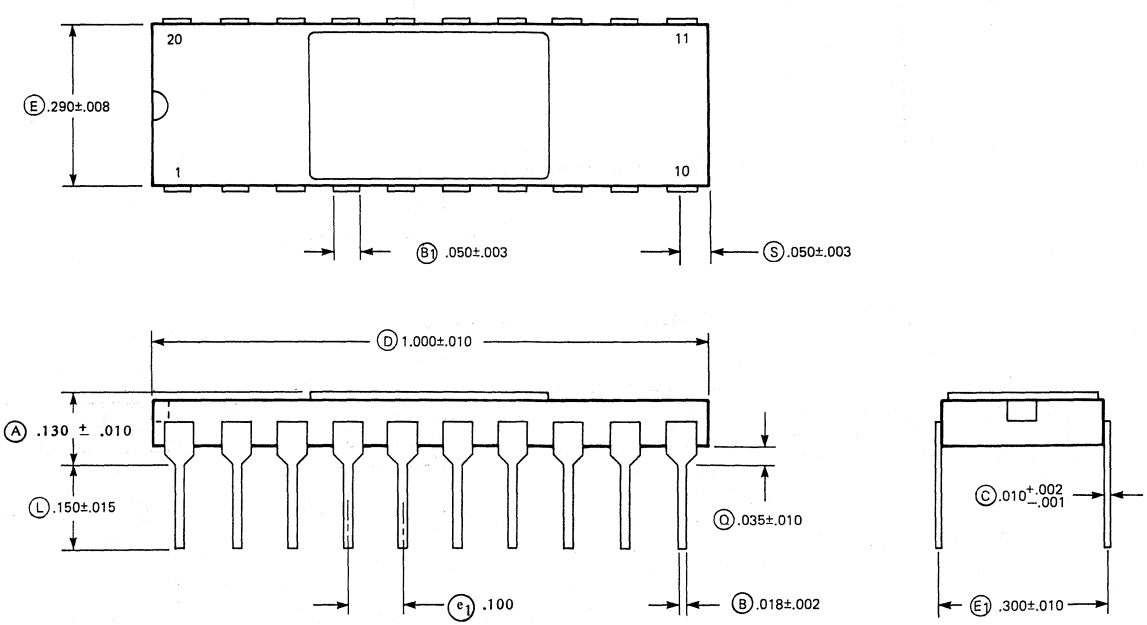


16-Lead Ceramic Side-Brazed Package

Note: Circle (e.g., Ⓑ) indicates JEDEC Reference.

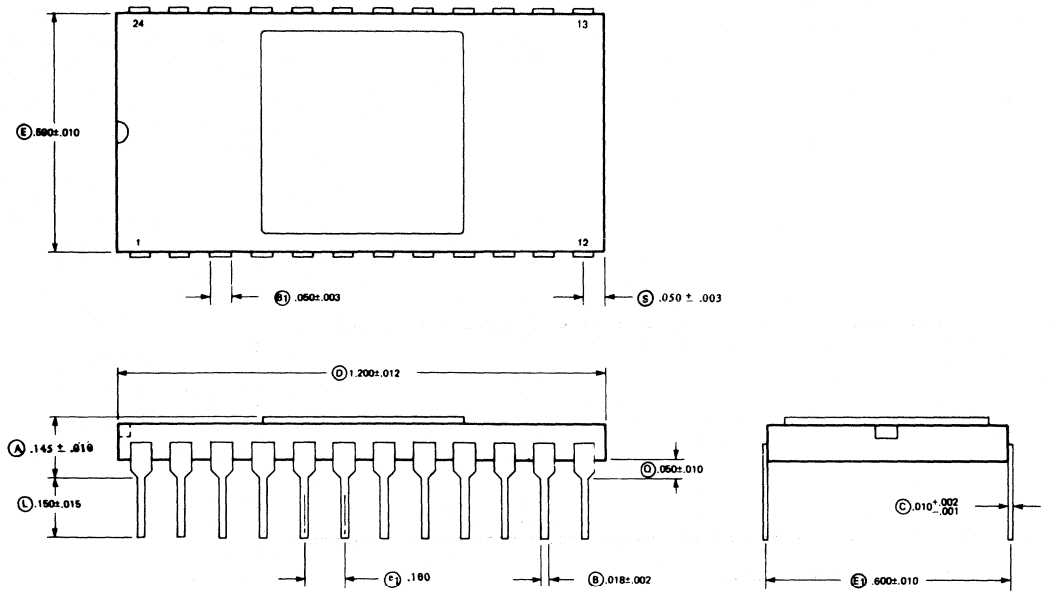


18-Lead Ceramic Side-Brazed Package

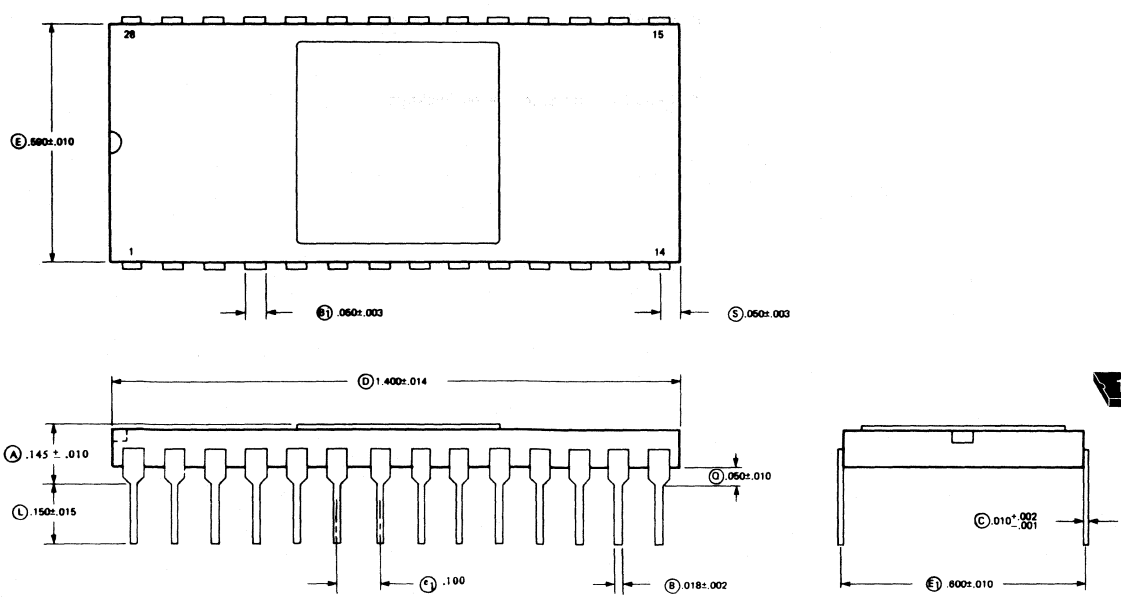


20-Lead Ceramic Side-Brazed Package

Note: Circle (e.g., (B)) indicates JEDEC Reference.

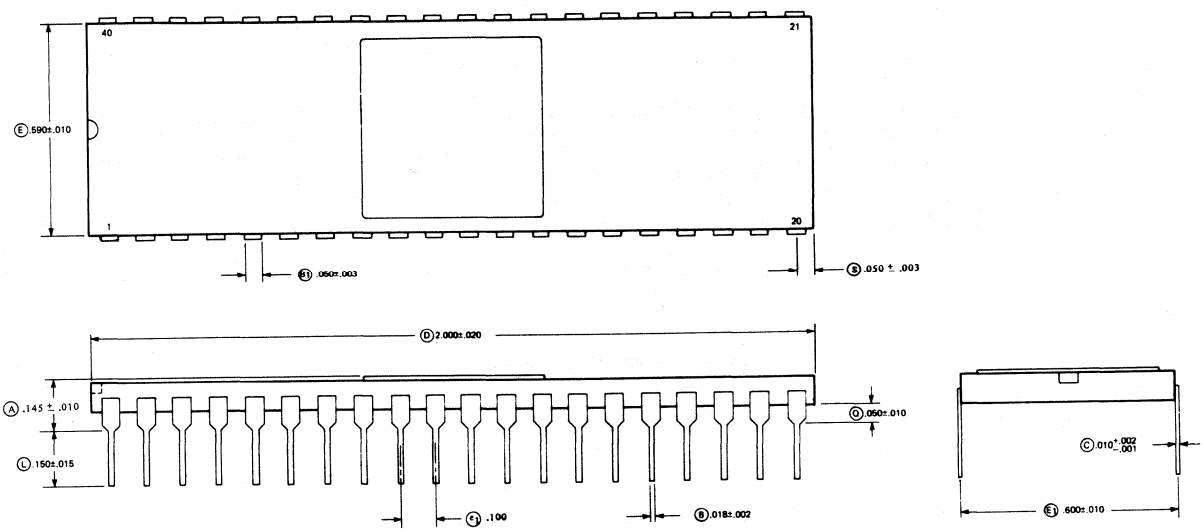


24-Lead Ceramic Side-Brazed Package



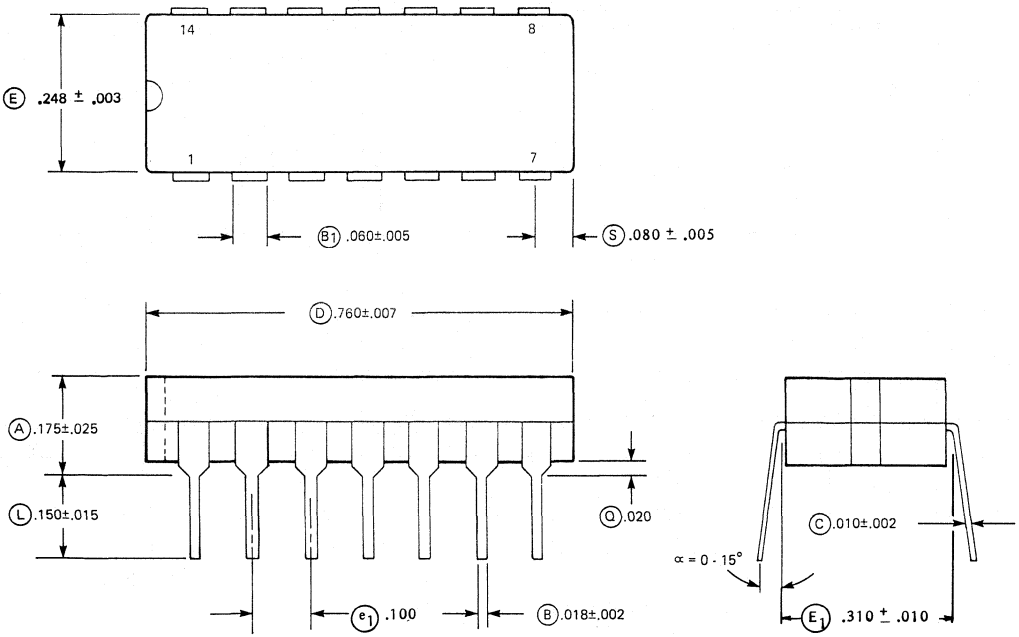
28-Lead Ceramic Side-Brazed Package

Note: Circle (e.g., (B)) indicates JEDEC Reference.

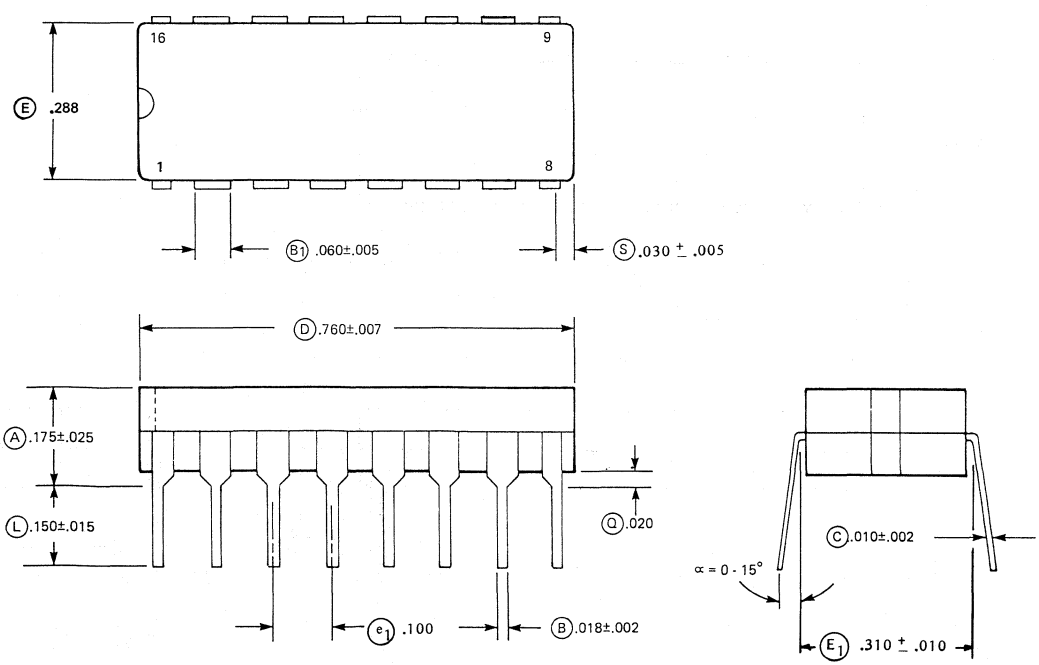


40-Lead Ceramic Side-Brazed Package

Note: Circle (e.g., (B)) indicates JEDEC Reference.

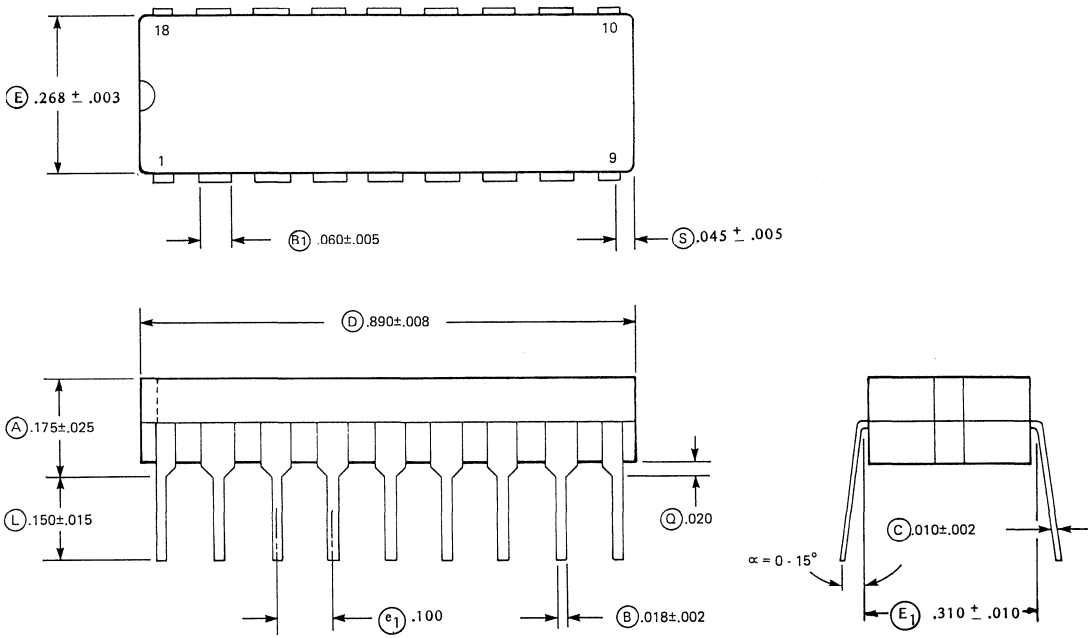


14-Lead CERDIP Package

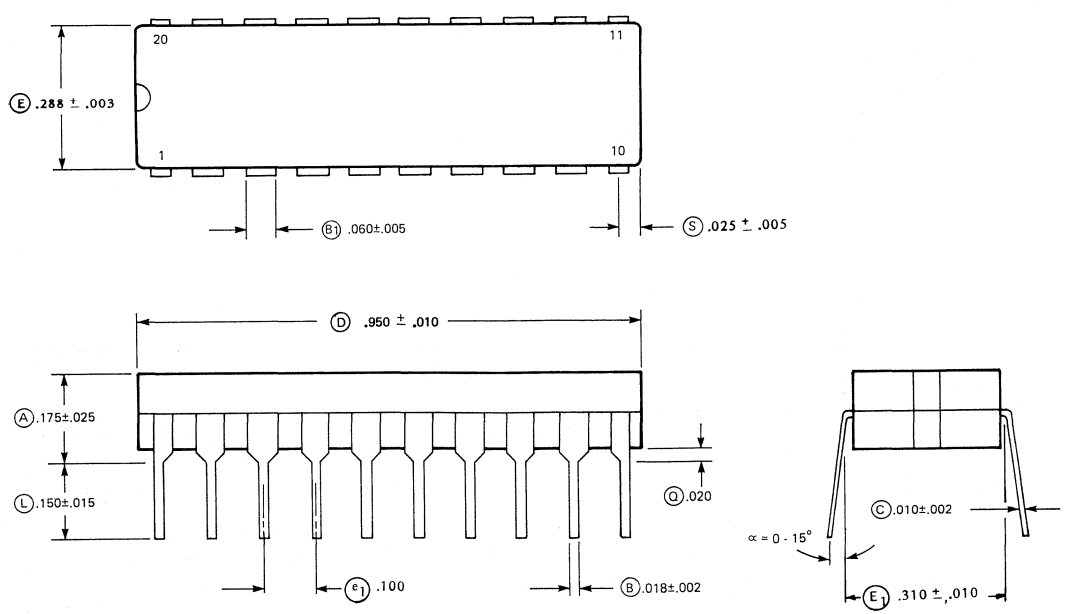


16-Lead CERDIP Package

Note: Circle (e.g., Ⓑ) indicates SEMI-STANDARD G1.1 STD.1.

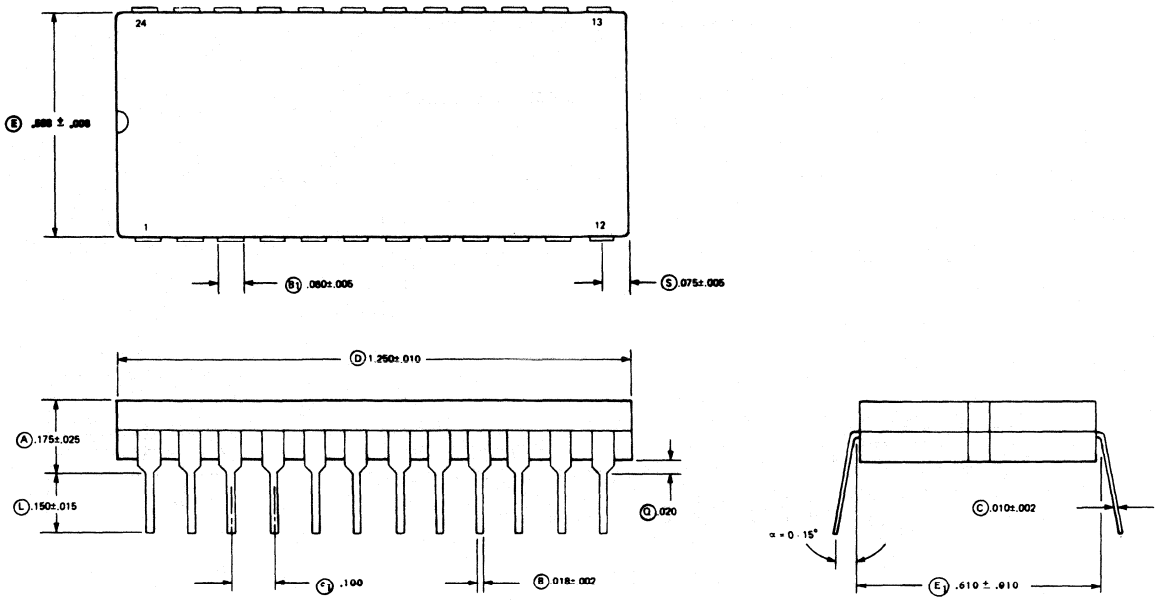


18-Lead CERDIP Package

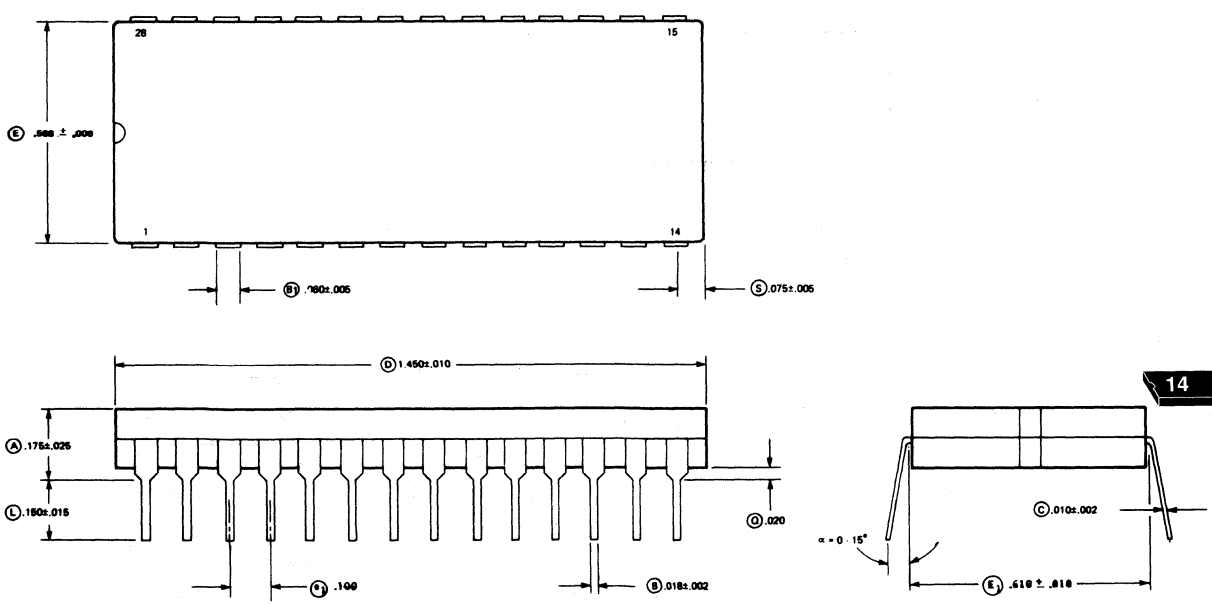


20-Lead CERDIP Package

Note: Circle (e.g., Ⓑ) indicates SEMI-STANDARD G1.1 STD.1.

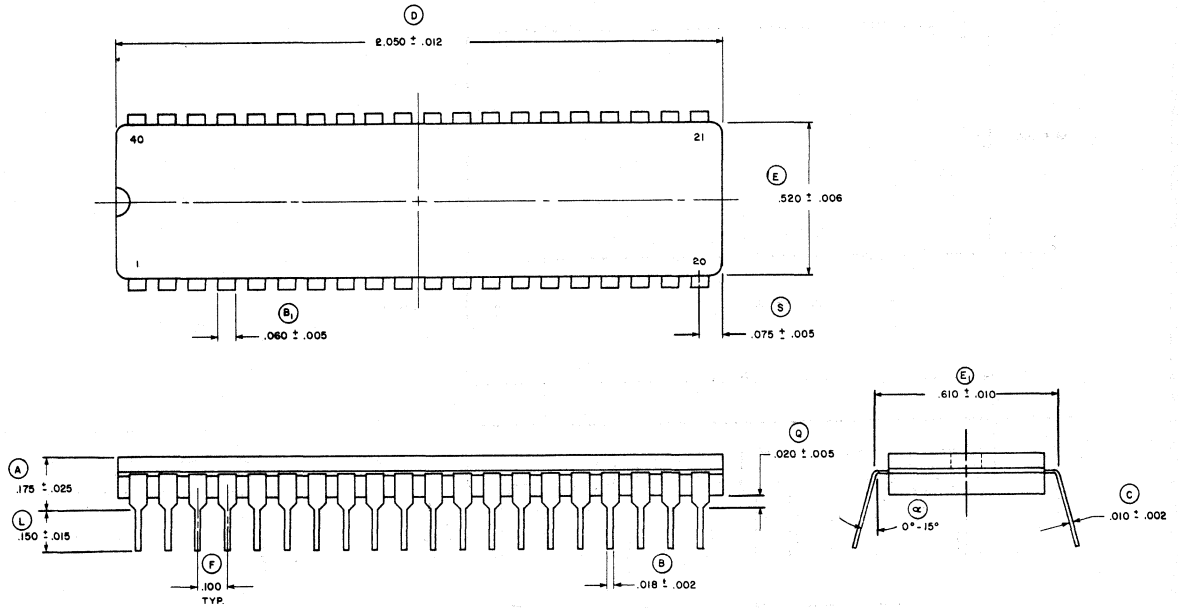


24-Lead CERDIP Package

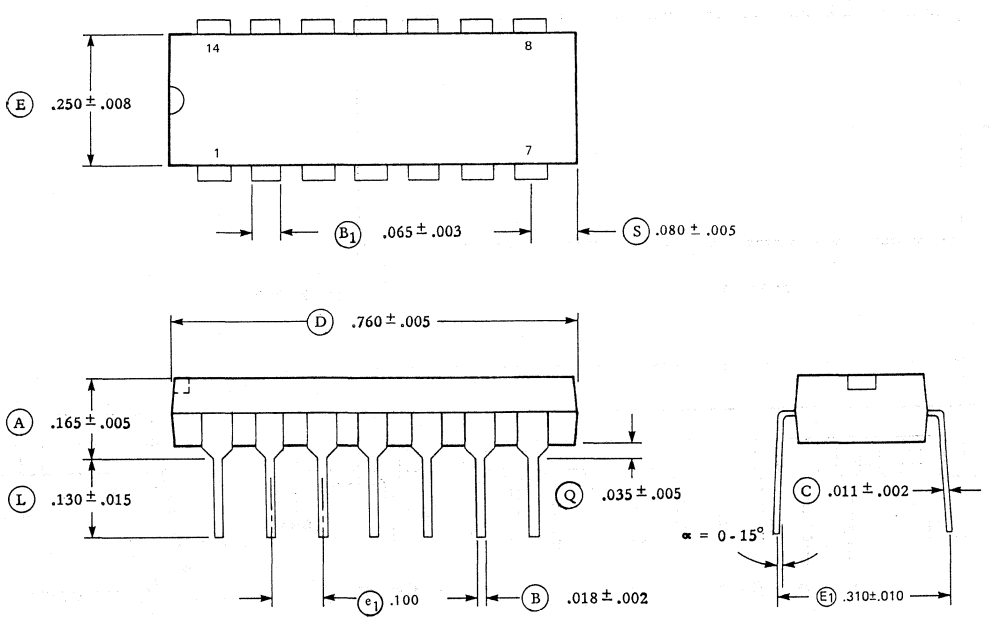


28-Lead CERDIP Package

Note: Circle (e.g., (B)) indicates SEMI-STANDARD G1.1 STD.1.

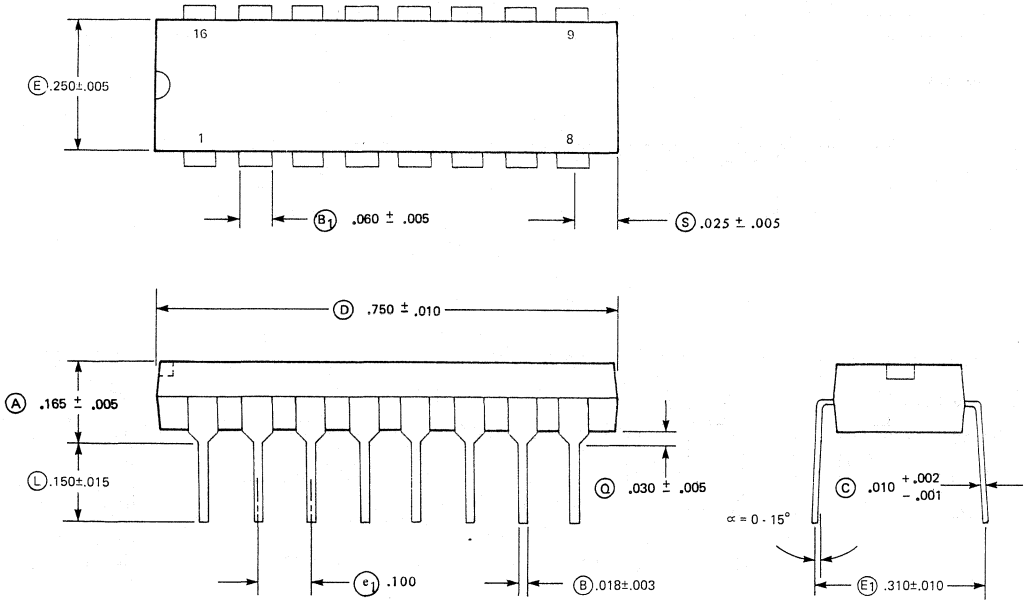


40-Lead CERDIP Package

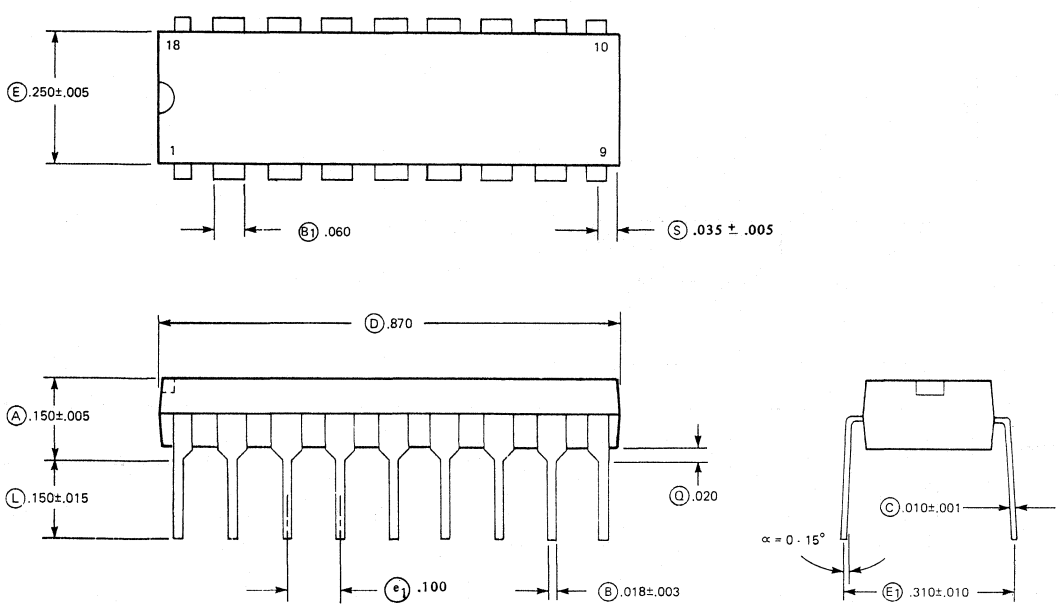


14-Lead Plastic Dual-In-Line Package

Note: Circle (e.g., (B)) indicates JEDEC Reference.

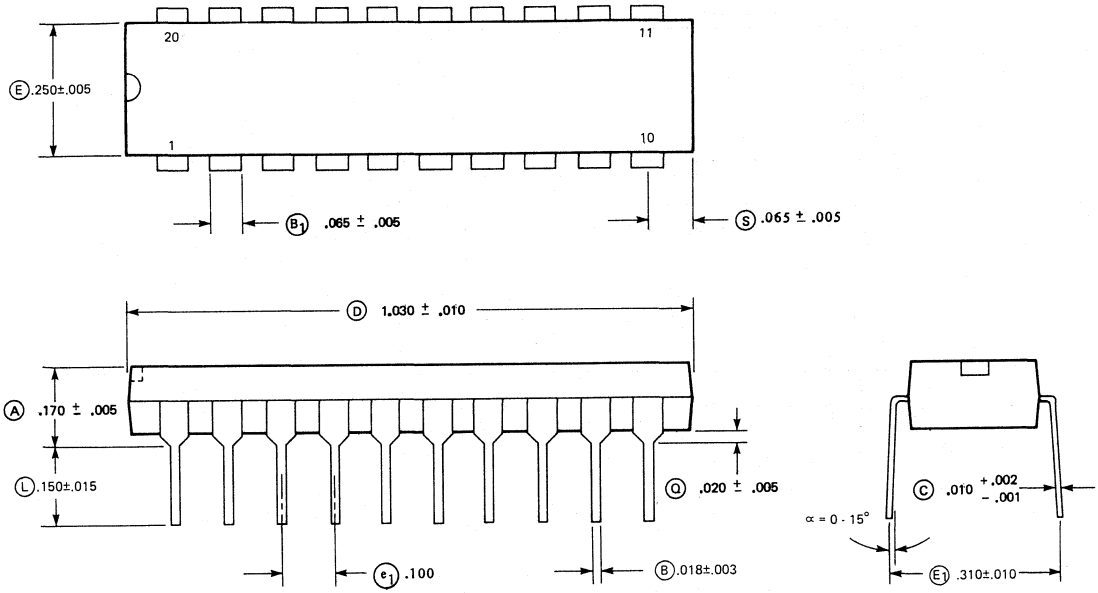


16-Lead Plastic Dual-In-Line Package

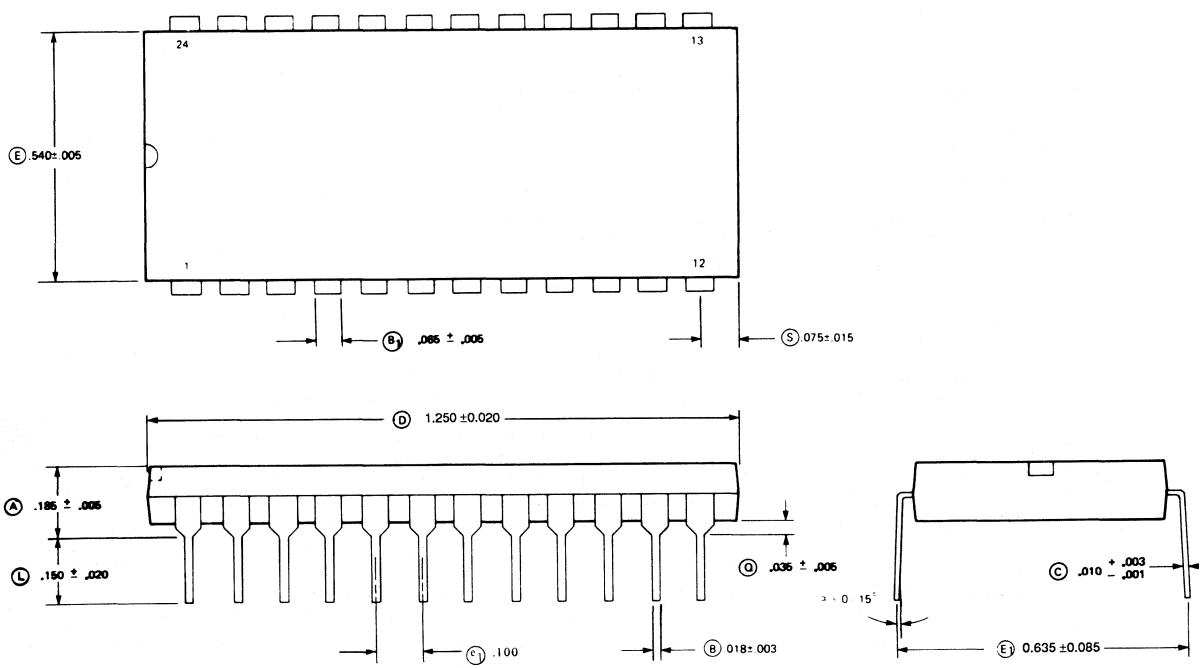


18-Lead Plastic Dual-In-Line Package

Note: Circle (e.g., (B)) indicates JEDEC Reference.

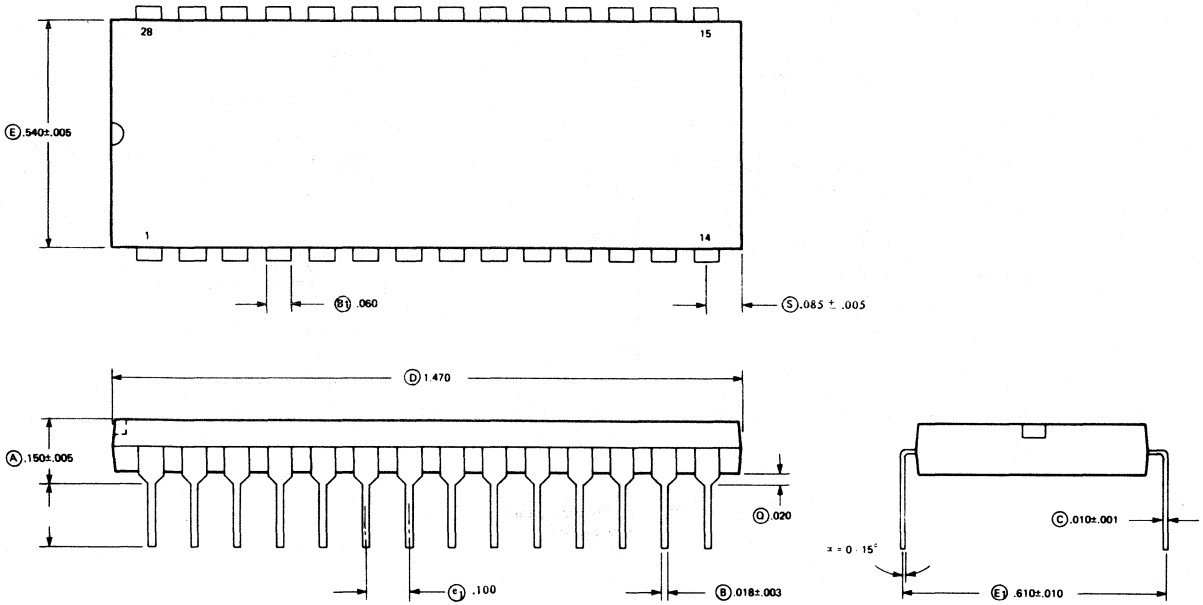


20-Lead Plastic Dual-In-Line Package

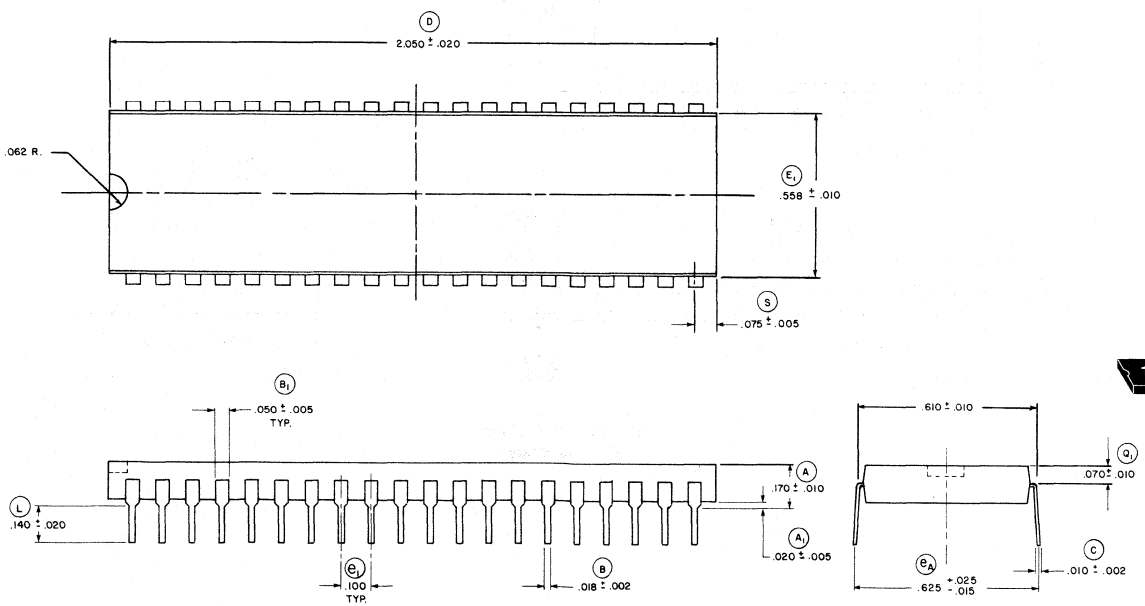


24-Lead Plastic Dual-In-Line Package

Note: Circle (e.g., Ⓑ) indicates JEDEC Reference.

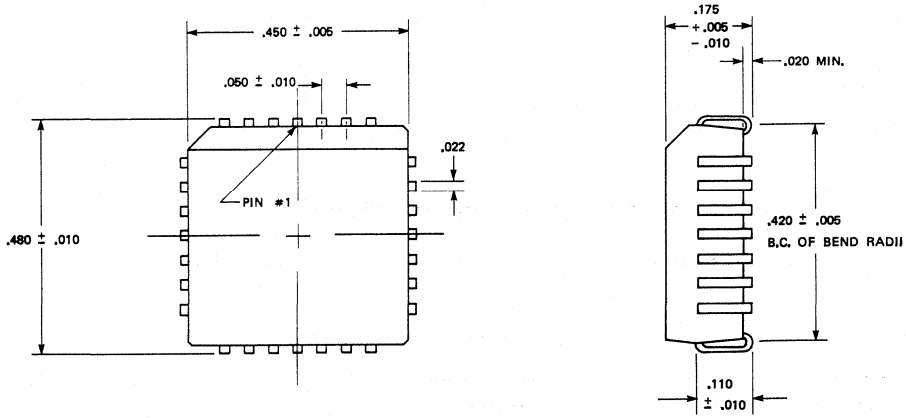


28-Lead Plastic Dual-In-Line Package

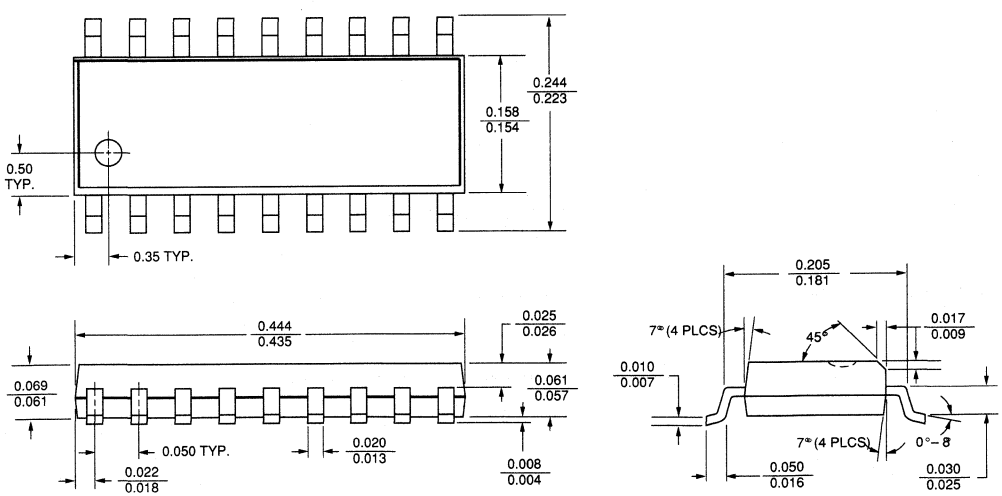


40-Lead Plastic DIP

Note: Circle (e.g., (B)) indicates JEDEC Reference.

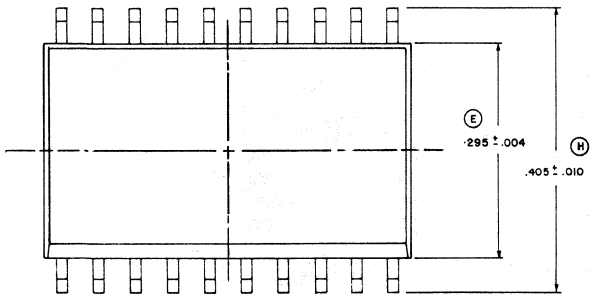


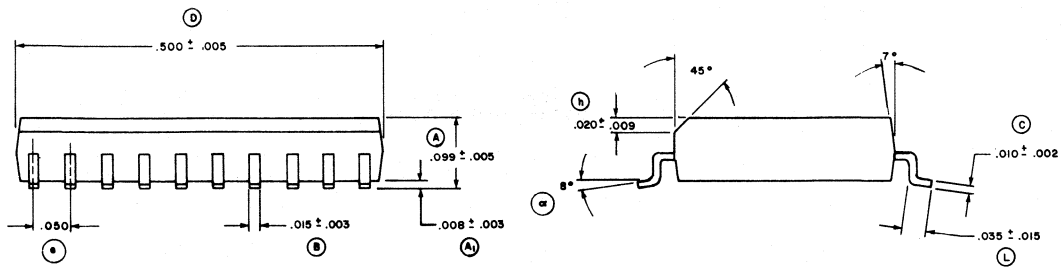
28-Lead Plastic Quad
"J" Bend



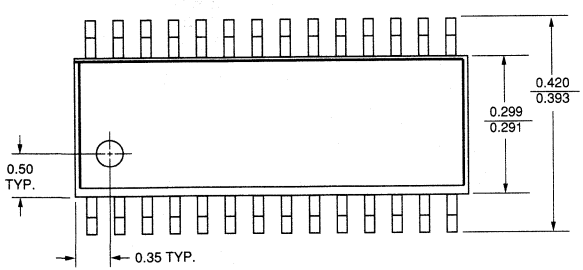
18-Lead SO Package
(Narrow Body)

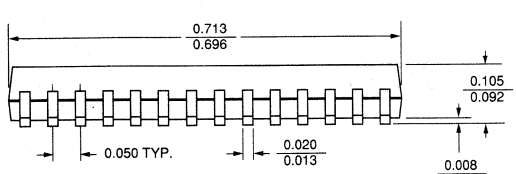
Note: Circle (e.g., (B)) indicates JEDEC Reference.

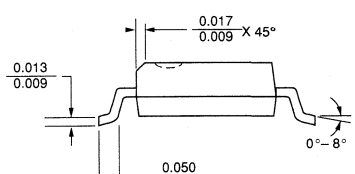




20-Lead SOW Package

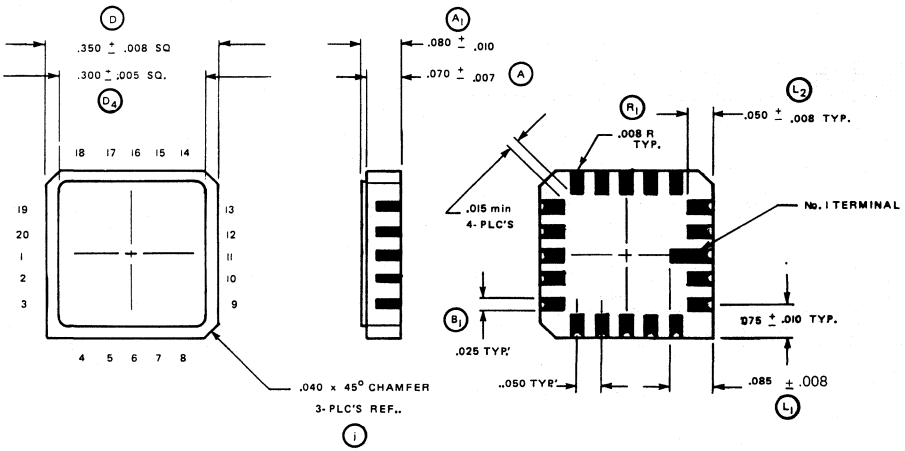




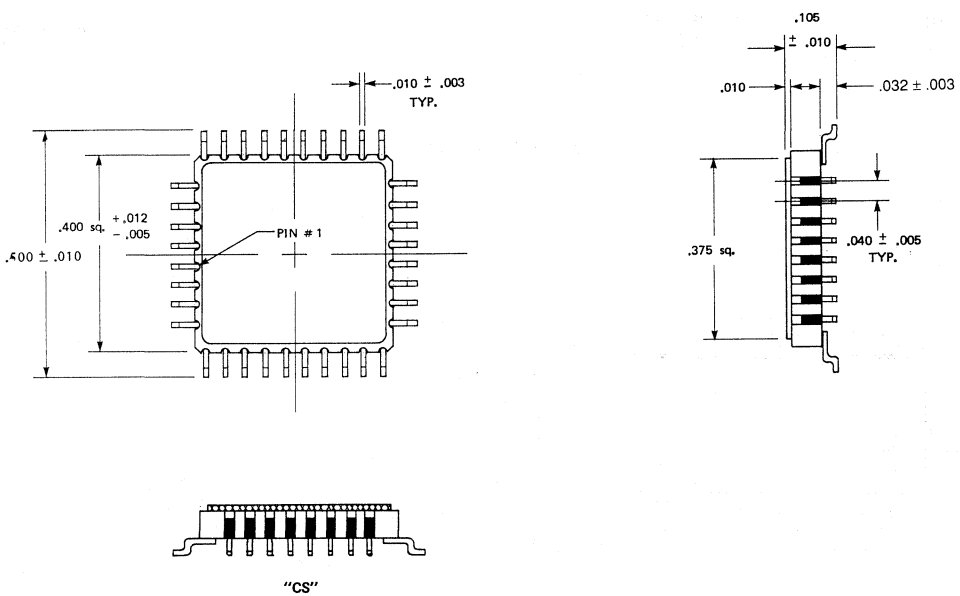


28-Lead SOW Package
(Wide Body)

Note: Circle (e.g. Ⓑ) indicates JEDEC Reference.

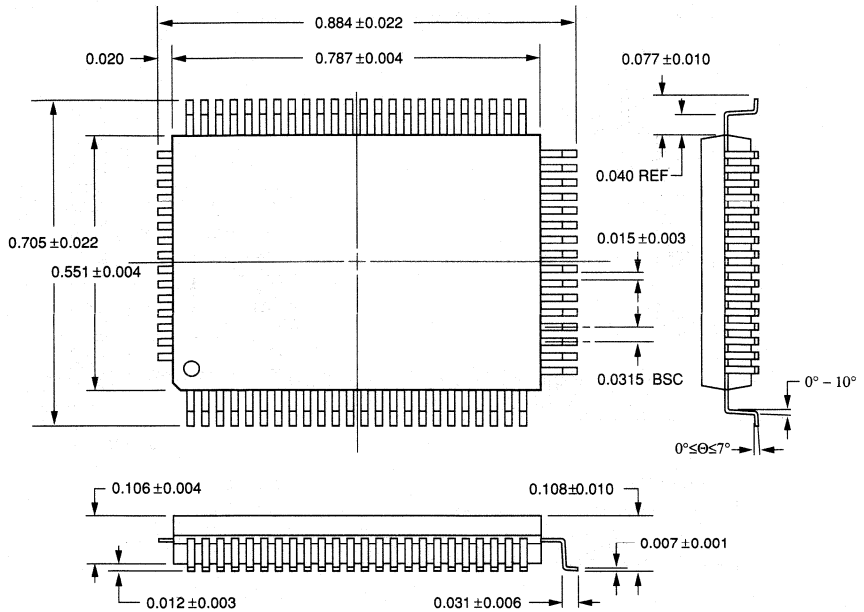


Type "C" Leadless
20-Terminal Chip Carrier

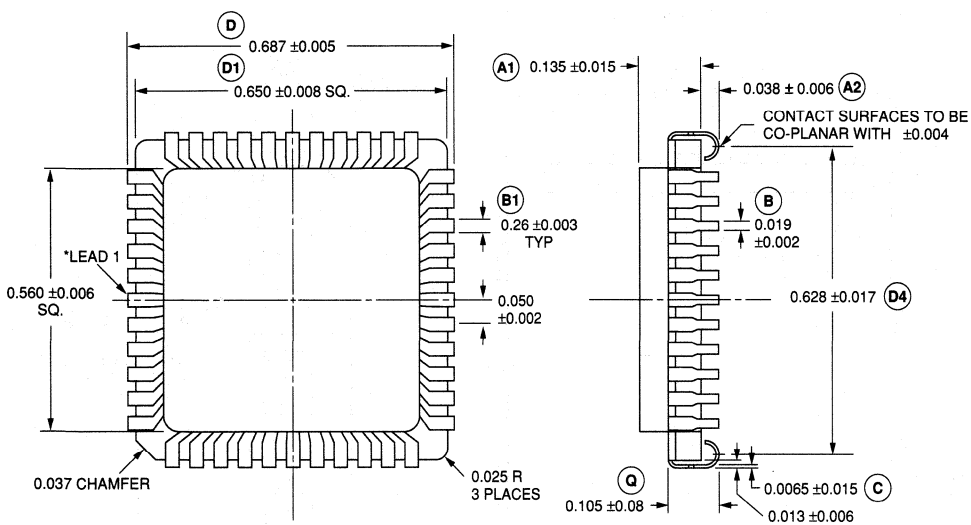


36-Leaded C/C
Bend Option "CS"

Note: Circle (e.g., (B)) indicates JEDEC Reference.



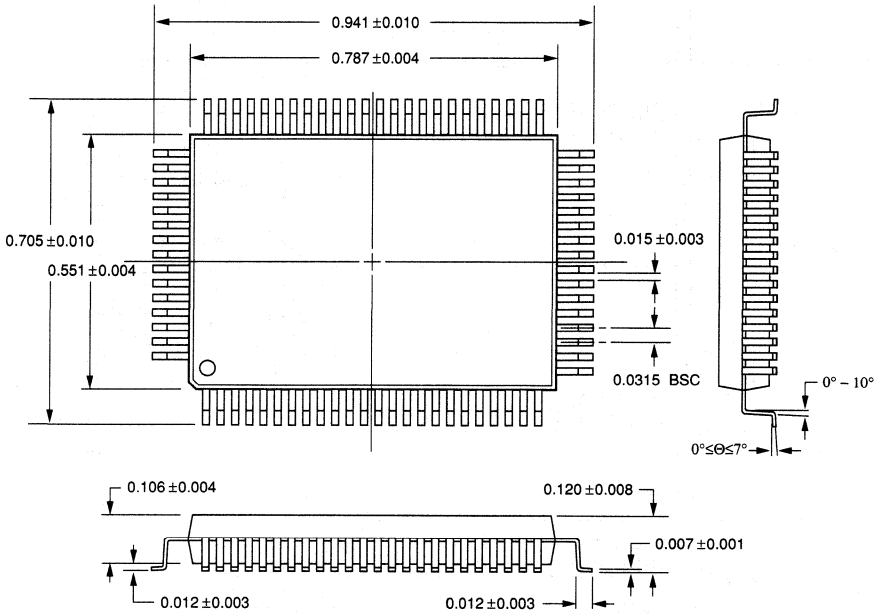
64-Lead 3-Sided Ceramic Quad Flat Package
("Gullwing" Package)



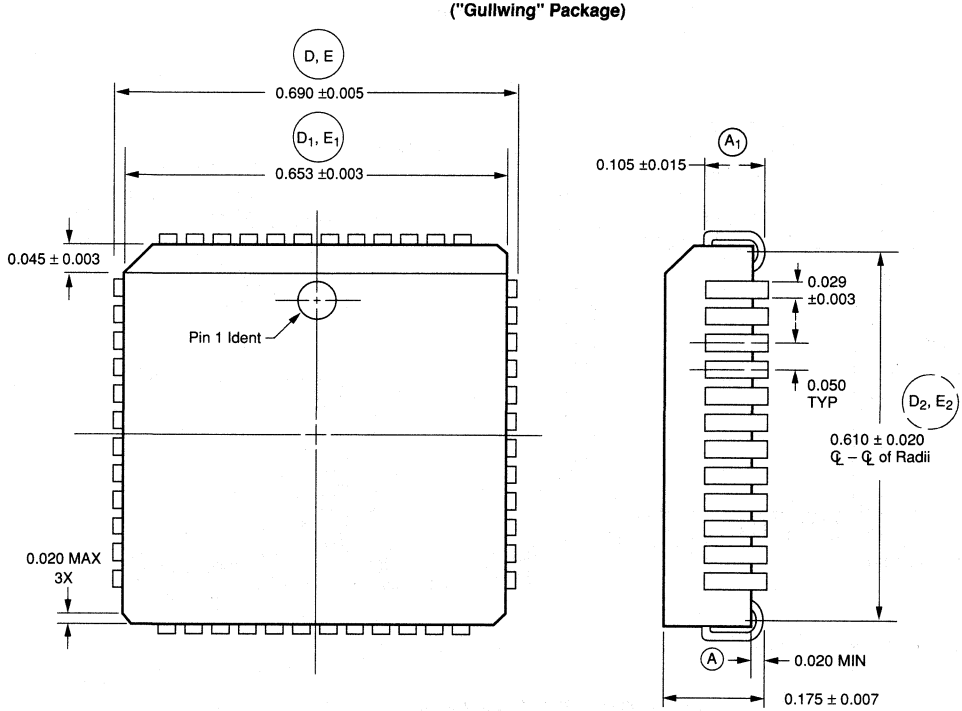
* I_{IO} applies to gold lead package only

44-Lead Quad CERPAC "DJ" Package

Note: Circle (e.g. Ⓑ) indicates JEDEC Reference.

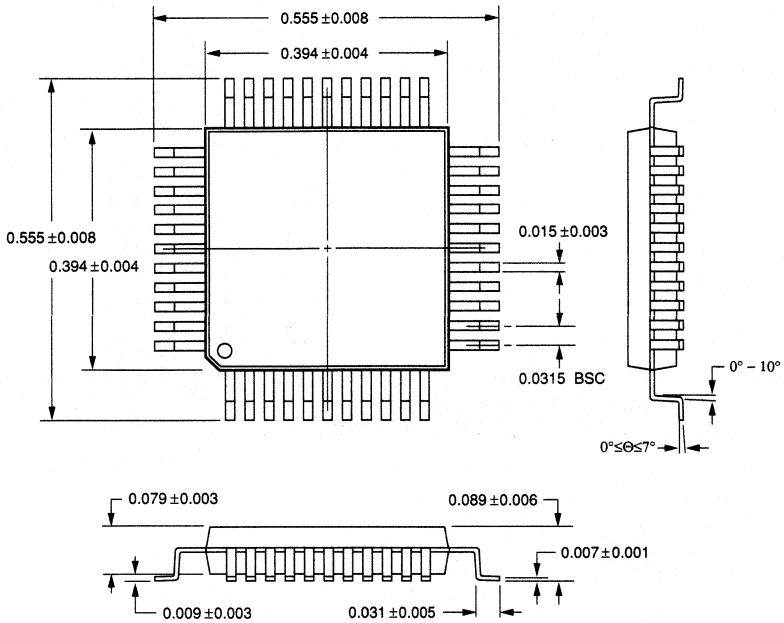


80-Lead Ceramic Quad Flat Package
("Gullwing" Package)

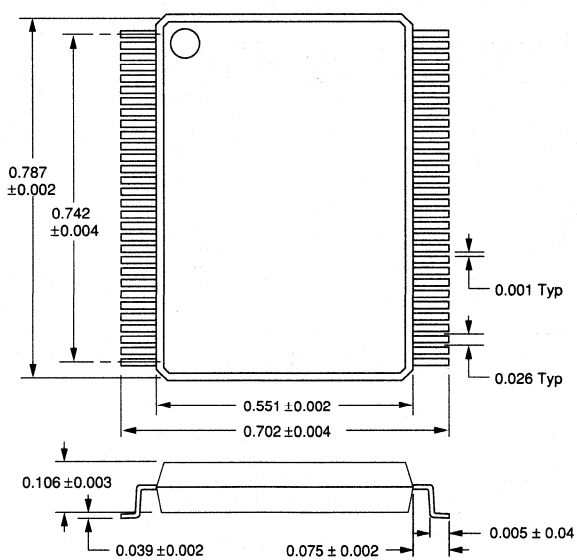


44-Lead Plastic "J " - Bend

Note: Circle (e.g. Ⓑ) indicates JEDEC Reference.

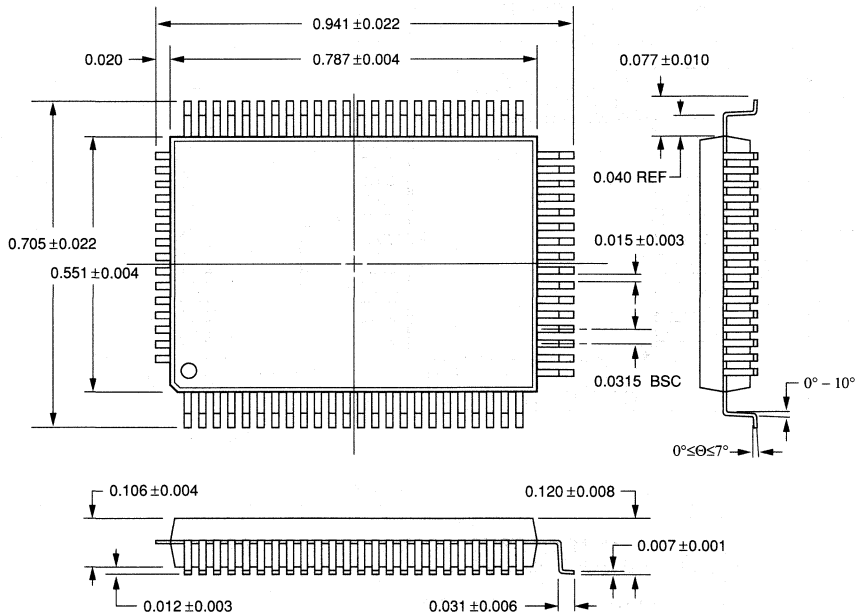


44-Lead Plastic Quad Flat Package
("Gullwing" Package)

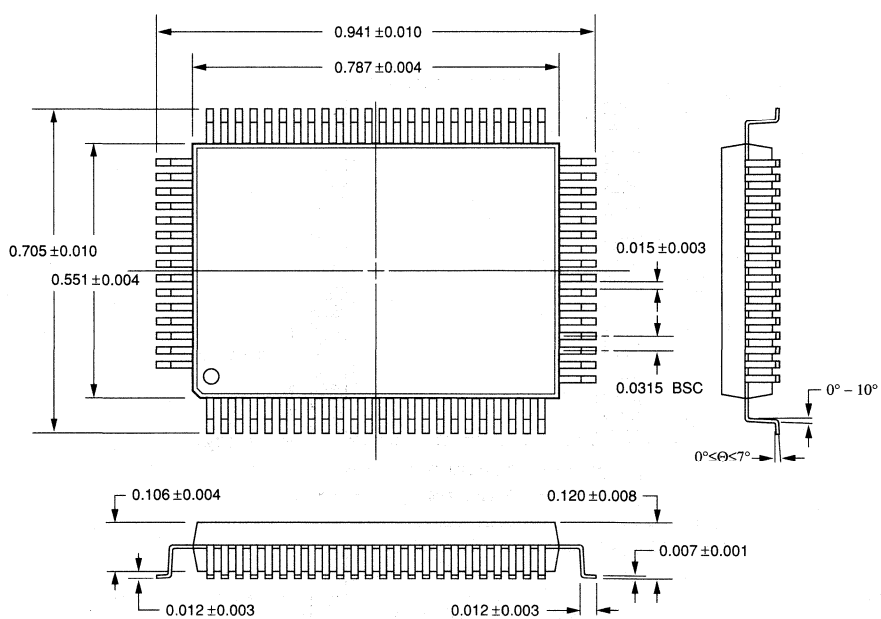


60-Lead Quad Plastic "PL" Package
("Gullwing" Package)

Note: Circle (e.g. Ⓑ) indicates JEDEC Reference.

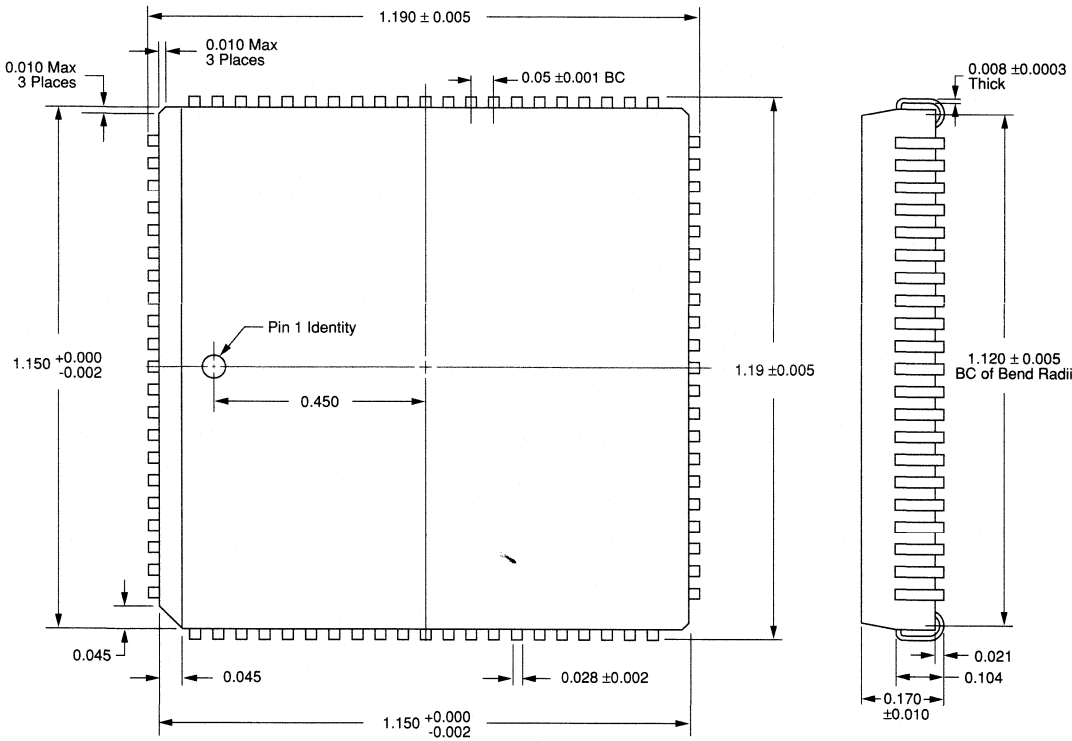


64-Lead 3-sided Plastic Quad Flat Package
("Gullwing" Package)



80-Lead Plastic Quad Flat Package
("Gullwing" Package)

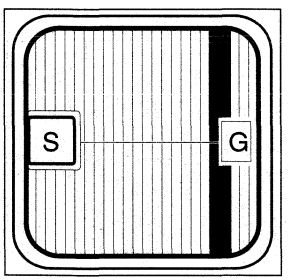
Note: Circle (e.g. Ⓑ) indicates JEDEC Reference.



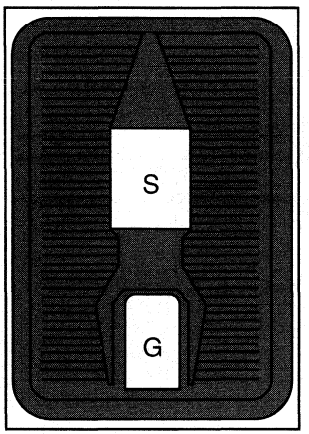
84-Lead Quad Plastic Chip Carrier

Note: Circle (e.g. Ⓑ) indicates JEDEC Reference.

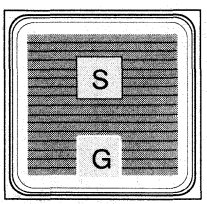
VF01



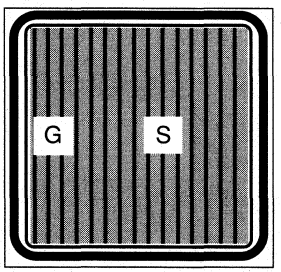
VF06



VF21



VF25

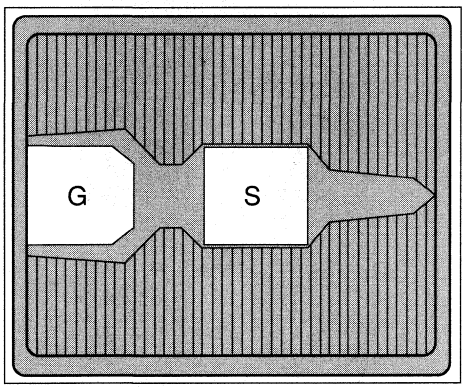


All dimensions in mils.

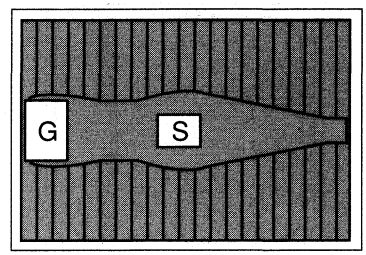
Die Geometry	Dimensions			Backside[2] Metal	Bonding Pads[3]		Recommended Assembly Material		
	Length[1]	Width	Thickness		Material	Size	Wire[4]	Wire Size[4]	Preform[5]
VF01	42	42	11 ± 1.5	Au	Al-Cu-Si	5 x 5	Al	1.3	Au - Si Eutectic
VF06	70	50	11 ± 1.5	Au	Al-Cu-Si	8 x 15	Al	1.5	Au - Si Eutectic
VF21	30	30	11 ± 1.5	Au	Al-Cu-Si	6 x 5.5	Al	1.3	Au - Si Eutectic
VF25	45	45	11 ± 1.5	Au	Al-Cu-Si	6.4 x 6.6	Al	1.5	Au - Si Eutectic

Notes:
1. Maximum values
2. Standard Au back is alloyed for optimum eutectic die attach. Cr-Ag backing is optional.
3. Al-Cu-Si is used for higher operating current densities. Bond pad size represents smaller gate pad.
4. Bond wire size and material depends on AuTCB, TSB or Al VSB.
5. Soft solder or organic die attach methods may be used with appropriate backmetal option.

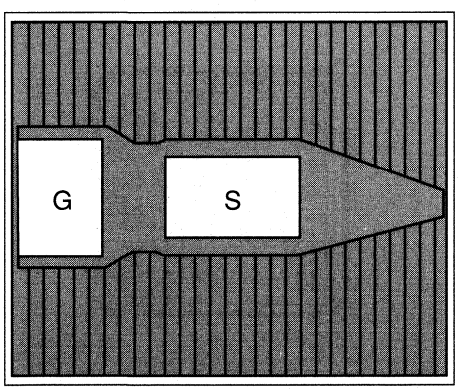
VF03



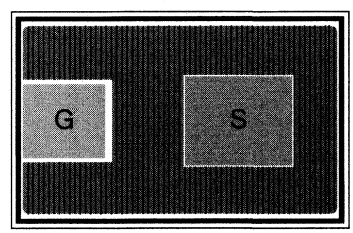
VF11



VF12



VF22

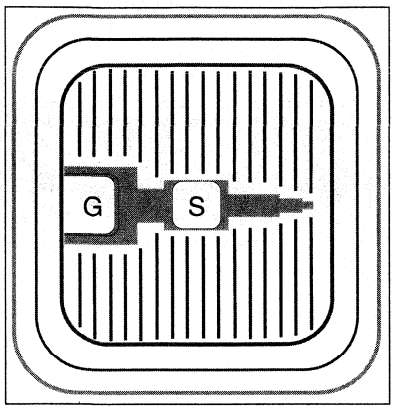


All dimensions in mils.

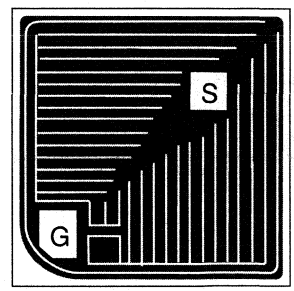
Die Geometry	Dimensions			Backside[2] Metal	Bonding Pads[3]		Recommended Assembly Material		
	Length[1]	Width	Thickness		Material	Size	Wire[4]	Wire Size[4]	Preform[5]
VF03	146	118	11 ± 1.5	Au	Al-Cu-Si	15 x 20	Al	5	Au-Si Eutectic
VF11	104	70	11 ± 1.5	Au	Al-Cu-Si	17.5 x 11	Al	5	Au-Si Eutectic
VF12	146	118	11 ± 1.5	Au	Al-Cu-Si	40 x 24	Al	5	Au-Si Eutectic
VF22	105	70	11 ± 1.5	Au	Al-Cu-Si	20 x 27	Al	5	Au-Si Eutectic

Notes:
1. Maximum values
2. Standard Au back is alloyed for optimum eutectic die attach. Cr-Ag backing is optional.
3. Al-Cu-Si is used for higher operating current densities. Bond pad size represents smaller gate pad.
4. Bond wire size and material depends on AuTCB, TSB or Al VSB.
5. Soft solder or organic die attach methods may be used with appropriate backmetal option.

VF05



VF13

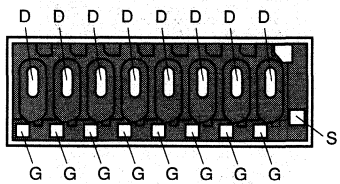


All dimensions in mils.

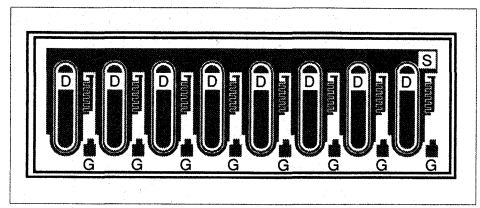
Die Geometry	Dimensions			Backside[2] Metal	Bonding Pads[3]		Recommended Assembly Material		
	Length[1]	Width	Thickness		Material	Size	Wire[4]	Wire Size[4]	Preform[5]
VF05	43	41	11 + 1.5	Au	Al-Cu-Si	5 x 5	Al	1.3	Au-Si Eutectic
VF13	30	30	11 + 1.5	Au	Al-Cu-Si	4 x 4	Al	1.3	Au-Si Eutectic

Notes:
1. Maximum values
2. Standard Au back is alloyed for optimum eutectic die attach. Cr-Ag backing is optional.
3. Al-Cu-Si is used for higher operating current densities. Bond pad size represents smaller gate pad.
4. Bond wire size and material depends on AuTCB, TSB or Al VSB.
5. Soft solder or organic die attach methods may be used with appropriate backmetal option.

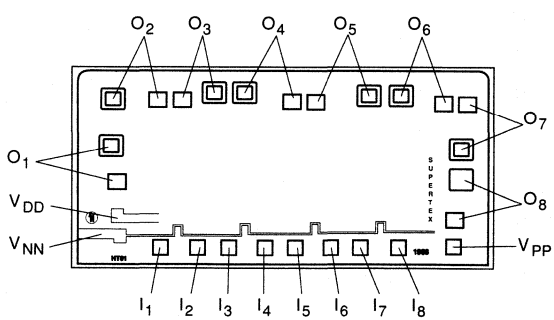
AF01



AF04



HT01

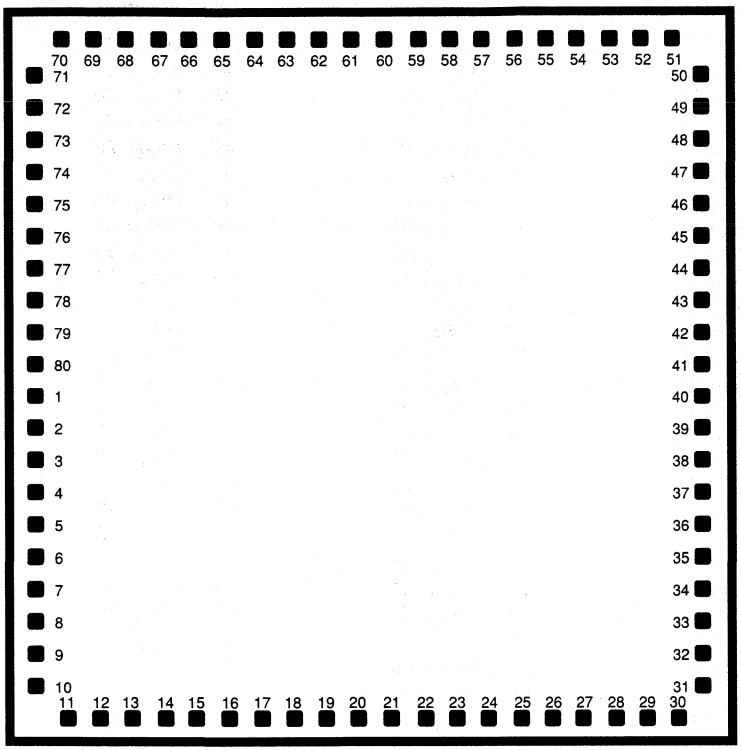


Note: Outputs O_2 thru O_8 each require two (2) wire bonds connected off-chip, as shown.

All dimensions in mils.

Die Geometry	Dimensions			Backside Metal	Bonding Pads		Recommended Assembly Material		
	Length	Width[1]	Thickness		Material	Size[2]	Wire[3]	Wire Size[3]	Preform
AF01	36	97	21 ± 1.5	None	Al-Si	4 x 4	Al	1.25	Epoxy
AF04[3]	48	146	21 ± 1.5	None	Al-Si	4 x 4	Al	1.25	Epoxy
HT01	68	136	21 ± 1.5	None	Al-Si	4 x 4	Al	1.25	Epoxy

Notes:
1. Maximum values
2. Bond pad size represents smallest pad.
3. Bond wire size and material depends on Au TCB, TSB or Al USB.
4. Preliminary information for AF04



Pad Coordinates in Microns

1	0; 1926	41	4448; 2158
2	0; 1712	42	4448; 2372
3	0; 1498	43	4448; 2586
4	0; 1284	44	4448; 2800
5	0; 1070	45	4448; 3014
6	0; 856	46	4448; 3228
7	0; 642	47	4448; 3442
8	0; 428	48	4448; 3656
9	0; 214	49	4448; 3870
10	0; 0	50	4448; 4084
11	200; -255	51	4248; 4339
12	414; -255	52	4034; 4339
13	628; -255	53	3820; 4339
14	842; -255	54	3606; 4339
15	1056; -255	55	3392; 4339
16	1270; -255	56	3178; 4339
17	1484; -255	57	2964; 4339
18	1698; -255	58	2750; 4339
19	1912; -255	59	2536; 4339
20	2126; -255	60	2322; 4339
21	2340; -255	61	2108; 4339
22	2554; -255	62	1894; 4339
23	2768; -255	63	1680; 4339
24	2982; -255	64	1466; 4339
25	3196; -255	65	1252; 4339
26	3410; -255	66	1038; 4339
27	3624; -255	67	824; 4333
28	3838; -255	68	610; 4339
29	4052; -255	69	396; 4333
30	4266; -255	70	182; 4339
31	4448; 0	71	0; 4084
32	4448; 214	72	0; 3870
33	4448; 446	73	0; 3638
34	4448; 660	74	0; 3424
35	4448; 874	75	0; 3210
36	4448; 1088	76	0; 2996
37	4448; 1302	77	0; 2782
38	4448; 1516	78	0; 2588
39	4448; 1730	79	0; 2354
40	4448; 1944	80	0; 2140

Die Specifications

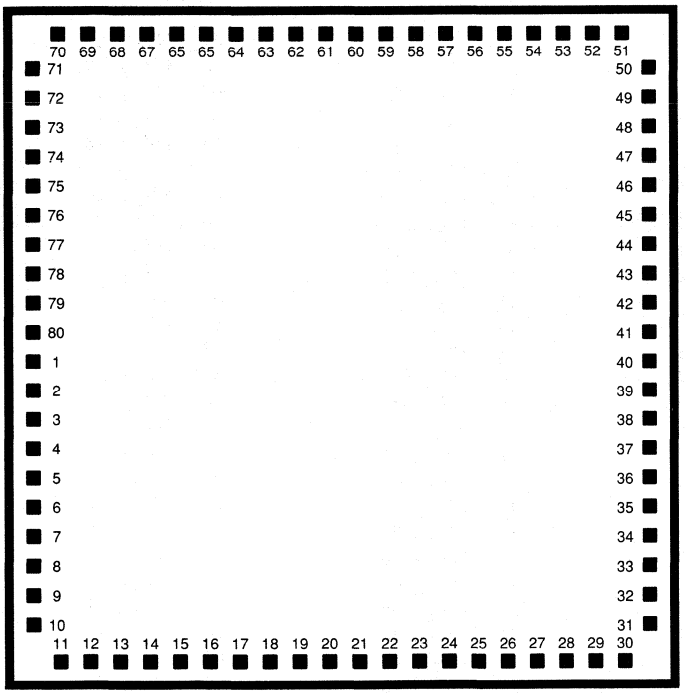
	mils	mm	
Die Size:	190 X 196	4.820 X 4.970	Back Side Metal: None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material: Epoxy Ablestick 84-1 or equal
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal: Al/Si
Bond Wire Size:	1.3	0.03	

HV03

Pin	Function	Pin	Function
1	V_{DD}	41	HV_{OUT} 33
2	$\overline{LE}$	42	HV_{OUT} 34
3	DATA IN	43	HV_{OUT} 35
4	$\overline{BL}$	44	HV_{OUT} 36
5	HV_{OUT} 1	45	HV_{OUT} 37
6	HV_{OUT} 2	46	HV_{OUT} 38
7	HV_{OUT} 3	47	HV_{OUT} 39
8	HV_{OUT} 4	48	HV_{OUT} 40
9	HV_{OUT} 5	49	HV_{OUT} 41
10	HV_{OUT} 6	50	HV_{OUT} 42
11	GND	51	GND
12	GND	52	GND
13	HV_{OUT} 7	53	HV_{OUT} 43
14	HV_{OUT} 8	54	HV_{OUT} 44
15	HV_{OUT} 9	55	HV_{OUT} 45
16	HV_{OUT} 10	56	HV_{OUT} 46
17	HV_{OUT} 11	57	HV_{OUT} 47
18	HV_{OUT} 12	58	HV_{OUT} 48
19	HV_{OUT} 13	59	HV_{OUT} 49
20	HV_{OUT} 14	60	HV_{OUT} 50
21	HV_{OUT} 15	61	HV_{OUT} 51
22	HV_{OUT} 16	62	HV_{OUT} 52
23	HV_{OUT} 17	63	HV_{OUT} 53
24	HV_{OUT} 18	64	HV_{OUT} 54
25	HV_{OUT} 19	65	HV_{OUT} 55
26	HV_{OUT} 20	66	HV_{OUT} 56
27	HV_{OUT} 21	67	HV_{OUT} 57
28	HV_{OUT} 22	68	HV_{OUT} 58
29	GND	69	GND
30	GND	70	GND
31	HV_{OUT} 23	71	HV_{OUT} 59
32	HV_{OUT} 24	72	HV_{OUT} 60
33	HV_{OUT} 25	73	HV_{OUT} 61
34	HV_{OUT} 26	74	HV_{OUT} 62
35	HV_{OUT} 27	75	HV_{OUT} 63
36	HV_{OUT} 28	76	HV_{OUT} 64
37	HV_{OUT} 29	77	$\overline{POL}$
38	HV_{OUT} 30	78	DATA OUT
39	HV_{OUT} 31	79	CLK
40	HV_{OUT} 32	80	GND

HV05

Pin	Function	Pin	Function
1	V_{DD}	41	HV_{OUT} 32
2	$\overline{LE}$	42	HV_{OUT} 31
3	DATA IN	43	HV_{OUT} 30
4	$\overline{BL}$	44	HV_{OUT} 29
5	HV_{OUT} 64	45	HV_{OUT} 28
6	HV_{OUT} 63	46	HV_{OUT} 27
7	HV_{OUT} 62	47	HV_{OUT} 26
8	HV_{OUT} 61	48	HV_{OUT} 25
9	HV_{OUT} 60	49	HV_{OUT} 24
10	HV_{OUT} 59	50	HV_{OUT} 23
11	GND	51	GND
12	GND	52	GND
13	HV_{OUT} 58	53	HV_{OUT} 22
14	HV_{OUT} 57	54	HV_{OUT} 21
15	HV_{OUT} 56	55	HV_{OUT} 20
16	HV_{OUT} 55	56	HV_{OUT} 19
17	HV_{OUT} 54	57	HV_{OUT} 18
18	HV_{OUT} 53	58	HV_{OUT} 17
19	HV_{OUT} 52	59	HV_{OUT} 16
20	HV_{OUT} 51	60	HV_{OUT} 15
21	HV_{OUT} 50	61	HV_{OUT} 14
22	HV_{OUT} 49	62	HV_{OUT} 13
23	HV_{OUT} 48	63	HV_{OUT} 12
24	HV_{OUT} 47	64	HV_{OUT} 11
25	HV_{OUT} 46	65	HV_{OUT} 10
26	HV_{OUT} 45	66	HV_{OUT} 9
27	HV_{OUT} 44	67	HV_{OUT} 8
28	HV_{OUT} 43	68	HV_{OUT} 7
29	GND	69	GND
30	GND	70	GND
31	HV_{OUT} 42	71	HV_{OUT} 6
32	HV_{OUT} 41	72	HV_{OUT} 5
33	HV_{OUT} 40	73	HV_{OUT} 4
34	HV_{OUT} 39	74	HV_{OUT} 3
35	HV_{OUT} 38	75	HV_{OUT} 2
36	HV_{OUT} 37	76	HV_{OUT} 1
37	HV_{OUT} 36	77	$\overline{POL}$
38	HV_{OUT} 35	78	DATA OUT
39	HV_{OUT} 34	79	CLK
40	HV_{OUT} 33	80	GND



Pad Coordinates in Microns

1	0; 1926	41	4448; 2158
2	0; 1712	42	4448; 2372
3	0; 1498	43	4448; 2586
4	0; 1284	44	4448; 2800
5	0; 1070	45	4448; 3014
6	0; 856	46	4448; 3228
7	0; 642	47	4448; 3442
8	0; 428	48	4448; 3656
9	0; 214	49	4448; 3870
10	0; 0	50	4448; 4084
11	200; -255	51	4248; 4339
12	414; -255	52	4034; 4339
13	628; -255	53	3820; 4339
14	842; -255	54	3606; 4339
15	1056; -255	55	3392; 4339
16	1270; -255	56	3178; 4339
17	1484; -255	57	2964; 4339
18	1698; -255	58	2750; 4339
19	1912; -255	59	2536; 4339
20	2126; -255	60	2322; 4339
21	2340; -255	61	2108; 4339
22	2554; -255	62	1894; 4339
23	2768; -255	63	1680; 4339
24	2982; -255	64	1466; 4339
25	3196; -255	65	1252; 4339
26	3410; -255	66	1038; 4339
27	3624; -255	67	824; 4339
28	3838; -255	68	610; 4339
29	4052; -255	69	396; 4339
30	4266; -255	70	182; 4339
31	4448; 0	71	0; 4084
32	4448; 214	72	0; 3870
33	4448; 446	73	0; 3638
34	4448; 660	74	0; 3424
35	4448; 874	75	0; 3210
36	4448; 1088	76	0; 2996
37	4448; 1302	77	0; 2782
38	4448; 1516	78	0; 2588
39	4448; 1730	79	0; 2354
40	4448; 1944	80	0; 2140

Die Specifications

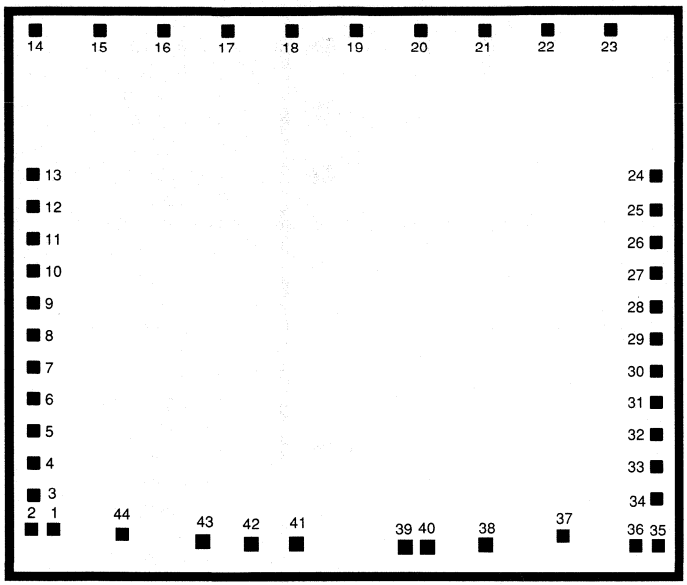
	mils	mm		
Die Size:	190 X 196	4.820 X 4.970	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 LMIS
Bond Pad Size:	4.5 X 4.5	0.11 X 0.11	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		

HV04/HV04H

Pin	Function	Pin	Function
1	V_{DD}	41	HV_{OUT} 33
2	$\overline{LE}$	42	HV_{OUT} 34
3	DATA IN	43	HV_{OUT} 35
4	$\overline{BL}$	44	HV_{OUT} 36
5	HV_{OUT} 1	45	HV_{OUT} 37
6	HV_{OUT} 2	46	HV_{OUT} 38
7	HV_{OUT} 3	47	HV_{OUT} 39
8	HV_{OUT} 4	48	HV_{OUT} 40
9	HV_{OUT} 5	49	HV_{OUT} 41
10	HV_{OUT} 6	50	HV_{OUT} 42
11	V_{PP}	51	V_{PP}
12	GND	52	GND
13	HV_{OUT} 7	53	HV_{OUT} 43
14	HV_{OUT} 8	54	HV_{OUT} 44
15	HV_{OUT} 9	55	HV_{OUT} 45
16	HV_{OUT} 10	56	HV_{OUT} 46
17	HV_{OUT} 11	57	HV_{OUT} 47
18	HV_{OUT} 12	58	HV_{OUT} 48
19	HV_{OUT} 13	59	HV_{OUT} 49
20	HV_{OUT} 14	60	HV_{OUT} 50
21	HV_{OUT} 15	61	HV_{OUT} 51
22	HV_{OUT} 16	62	HV_{OUT} 52
23	HV_{OUT} 17	63	HV_{OUT} 53
24	HV_{OUT} 18	64	HV_{OUT} 54
25	HV_{OUT} 19	65	HV_{OUT} 55
26	HV_{OUT} 20	66	HV_{OUT} 56
27	HV_{OUT} 21	67	HV_{OUT} 57
28	HV_{OUT} 22	68	HV_{OUT} 58
29	GND	69	GND
30	V_{PP}	70	V_{PP}
31	HV_{OUT} 23	71	HV_{OUT} 59
32	HV_{OUT} 24	72	HV_{OUT} 60
33	HV_{OUT} 25	73	HV_{OUT} 61
34	HV_{OUT} 26	74	HV_{OUT} 62
35	HV_{OUT} 27	75	HV_{OUT} 63
36	HV_{OUT} 28	76	HV_{OUT} 64
37	HV_{OUT} 29	77	$\overline{POL}$
38	HV_{OUT} 30	78	DATA OUT
39	HV_{OUT} 31	79	CLK
40	HV_{OUT} 32	80	GND

HV06/HV06H

Pin	Function	Pin	Function
1	V_{DD}	41	HV_{OUT} 32
2	$\overline{LE}$	42	HV_{OUT} 31
3	DATA IN	43	HV_{OUT} 30
4	$\overline{BL}$	44	HV_{OUT} 29
5	HV_{OUT} 64	45	HV_{OUT} 28
6	HV_{OUT} 63	46	HV_{OUT} 27
7	HV_{OUT} 62	47	HV_{OUT} 26
8	HV_{OUT} 61	48	HV_{OUT} 25
9	HV_{OUT} 60	49	HV_{OUT} 24
10	HV_{OUT} 59	50	HV_{OUT} 23
11	V_{PP}	51	V_{PP}
12	GND	52	GND
13	HV_{OUT} 58	53	HV_{OUT} 22
14	HV_{OUT} 57	54	HV_{OUT} 21
15	HV_{OUT} 56	55	HV_{OUT} 20
16	HV_{OUT} 55	56	HV_{OUT} 19
17	HV_{OUT} 54	57	HV_{OUT} 18
18	HV_{OUT} 53	58	HV_{OUT} 17
19	HV_{OUT} 52	59	HV_{OUT} 16
20	HV_{OUT} 51	60	HV_{OUT} 15
21	HV_{OUT} 50	61	HV_{OUT} 14
22	HV_{OUT} 49	62	HV_{OUT} 13
23	HV_{OUT} 48	63	HV_{OUT} 12
24	HV_{OUT} 47	64	HV_{OUT} 11
25	HV_{OUT} 46	65	HV_{OUT} 10
26	HV_{OUT} 45	66	HV_{OUT} 9
27	HV_{OUT} 44	67	HV_{OUT} 8
28	HV_{OUT} 43	68	HV_{OUT} 7
29	GND	69	GND
30	V_{PP}	70	V_{PP}
31	HV_{OUT} 42	71	HV_{OUT} 6
32	HV_{OUT} 41	72	HV_{OUT} 5
33	HV_{OUT} 40	73	HV_{OUT} 4
34	HV_{OUT} 39	74	HV_{OUT} 3
35	HV_{OUT} 38	75	HV_{OUT} 2
36	HV_{OUT} 37	76	HV_{OUT} 1
37	HV_{OUT} 36	77	$\overline{POL}$
38	HV_{OUT} 35	78	DATA OUT
39	HV_{OUT} 34	79	CLK
40	HV_{OUT} 33	80	GND



Pad Coordinates in Microns

1	187; 0	23	5004; 4415
2	0; 0	24	5395; 3129.5
3	16; 310	25	5395; 2846.5
4	16; 593	26	5395; 2563.5
5	16; 876	27	5395; 2280.5
6	16; 1159	28	5395; 1997.5
7	16; 1442	29	5395; 1714.5
8	16; 1442	30	5395; 1431.5
9	16; 1008	31	5395; 1148.5
10	16; 2291	32	5395; 865.5
11	16; 2574	33	5395; 582.5
12	16; 2857	34	5395; 299.5
13	16; 3140	35	5406; -108.5
14	36; 4415	36	5200; -108.5
15	588; 4415	37	4583.5; -29.5
16	1140; 4415.5	38	3902; -104.5
17	1692; 4415	39	3405.5; -131
18	2244; 4415	40	3206; -126
19	2796; 4415	41	2276; -104.5
20	3348; 4415	42	1878; -104.5
21	3900; 4415	43	1468; -98.5
22	4452; 4415	44	773.5; -30

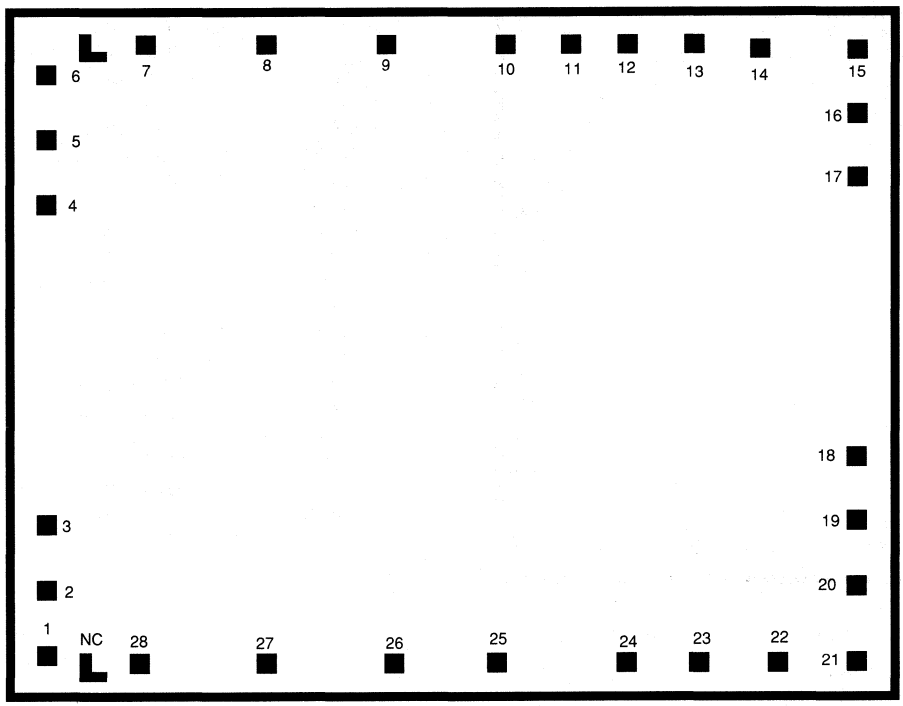
HV09

Pin	Function	Pin	Function	Pin	Function
1	HVGND	16	HV_{OUT} 14	31	HV_{OUT} 29
2	V_{PP}	17	HV_{OUT} 15	32	HV_{OUT} 30
3	HV_{OUT} 1	18	HV_{OUT} 16	33	HV_{OUT} 31
4	HV_{OUT} 2	19	HV_{OUT} 17	34	HV_{OUT} 32
5	HV_{OUT} 3	20	HV_{OUT} 18	35	V_{PP}
6	HV_{OUT} 4	21	HV_{OUT} 19	36	HVGND
7	HV_{OUT} 5	22	HV_{OUT} 20	37	DATA I/O B
8	HV_{OUT} 6	23	HV_{OUT} 21	38	POLARITY
9	HV_{OUT} 7	24	HV_{OUT} 22	39	V_{DD}
10	HV_{OUT} 8	25	HV_{OUT} 23	40	DIRECTION
11	HV_{OUT} 9	26	HV_{OUT} 24	41	V_{SS}
12	HV_{OUT} 10	27	HV_{OUT} 25	42	CLK
13	HV_{OUT} 11	28	HV_{OUT} 26	43	OUTPUT ENABLE
14	HV_{OUT} 12	29	HV_{OUT} 27	44	DATA I/O A
15	HV_{OUT} 13	30	HV_{OUT} 28		

Notes:
1. See datasheet for HV_{OUT} dependence on DIR
2. Backside is V_{PP}

Die Specifications

	mils	mm		
Die Size:	198 X 230	5.020 X 5.840	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 or Equal
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		



Pad Coordinates in Microns

1	0; 0
2	0; 378
3	0; 756
4	0; 2640
5	0; 3018
6	0; 3396
7	565; 3565
8	1265; 3565
9	1965 ; 3565
10	2665; 3565
11	3043; 3565
12	3368; 3565
13	3746; 3565
14	4124; 3535
15	4689; 3529
16	4689; 3151
17	4689; 2773
18	4689; 1150
19	4689; 772
20	4689; 394
21	4689; -49
22	4235; -49
23	3781; -49
24	3365; -49
25	2615; -49
26	2015; -49
27	1265; -49
28	535; -49

Die Specifications

	mils	mm		
Die Size:	210 X 159	5.330 X 4.030	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 LMIS
Bond Pad Size:	4.5 X 4.5	0.11 X 0.11	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		

HV10

Pin	Function
1	SW1
2	SW0
3	SW0
4	V_{DD}
5	GND
6	LE
7	N/C
8	$\overline{C0}$
9	$\overline{C1}$
10	N/C
11	N/C
12	N/C
13	$\overline{C2}$
14	N/C
15	$\overline{C3}$
16	V_{NN}
17	CL
18	V_{PP}
19	SW3
20	SW3
21	N/C
22	SW2
23	N/C
24	N/C
25	SW2
26	N/C
27	SW1
28	N/C

HV12

Pin	Function
1	N/C
2	Y2
3	Y3
4	Y4
5	Y5
6	N/C
7	Y6
8	N/C
9	Y7
10	N/C
11	N/C
12	D_{OUT}
13	CL
14	N/C
15	LE
16	CK
17	D_{IN}
18	N/C
19	V_{DD}
20	GND
21	V_{NN}
22	V_{PP}
23	N/C
24	YC
25	N/C
26	Y0
27	N/C
28	Y1

HV14

Pin	Function
1	N/C
2	Y6
3	Y4
4	V_{DD}
5	Y2
6	Y1
7	N/C
8	Y0
9	N/C
10	Y3
11	N/C
12	A
13	B
14	N/C
15	C
16	CL
17	D_{IN}
18	N/C
19	V_{PP}
20	$\overline{CS2}$
21	GND
22	V_{NN}
23	$\overline{CS1}$
24	Y5
25	N/C
26	Y7
27	N/C
28	YC

HV15

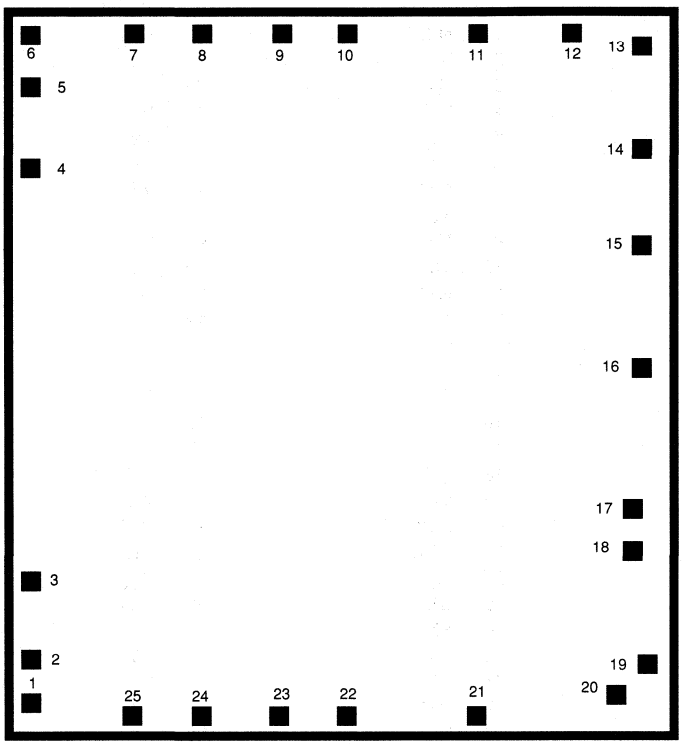
Pin	Function
1	N/C
2	Y6
3	Y4
4	V_{DD}
5	Y2
6	N/C
7	Y1
8	Y0
9	N/C
10	Y3
11	N/C
12	A
13	B
14	N/C
15	C
16	CL
17	LE
18	N/C
19	V_{PP}
20	$\overline{CS2}$
21	GND
22	V_{NN}
23	$\overline{CS1}$
24	N/C
25	Y5
26	Y7
27	N/C
28	Y6

HV16

Pin	Function
1	N/C
2	SW3
3	SW3
4	SW4
5	SW4
6	SW5
7	N/C
8	SW5
9	SW6
10	N/C
11	SW6
12	SW7
13	SW7
14	D_{OUT}
15	LE
16	CK
17	D_{IN}
18	N/C
19	I_{DD}
20	GND
21	V_{NN}
22	V_{PP}
23	SW0
24	SW0
25	SW1
26	SW1
27	SW2
28	SW2

HV18

Pin	Function
1	N/C
2	SW3
3	SW3
4	SW4
5	SW4
6	SW5
7	SW5
8	SW6
9	SW6
10	SW7
11	SW7
12	D_{OUT}
13	CL
14	N/C
15	LE
16	CLK
17	D_{IN}
18	N/C
19	V_{DD}
20	GND
21	V_{NN}
22	V_{PP}
23	SW0
24	SW0
25	SW1
26	SW1
27	SW2
28	SW2



Pad Coordinates in Microns

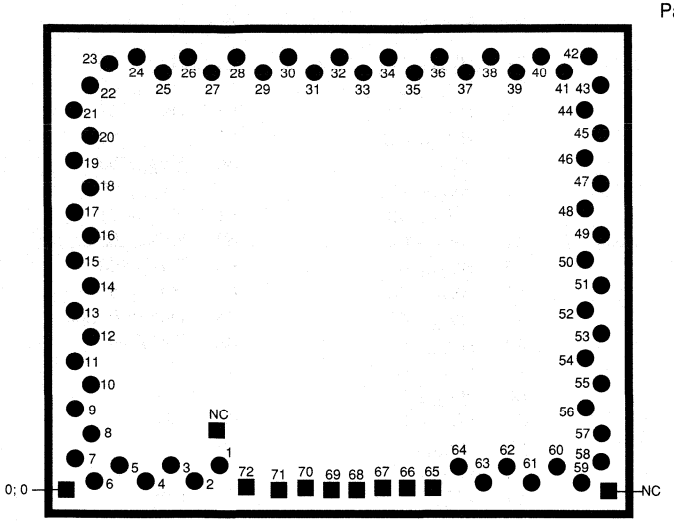
1	0; 0
2	-1; 302.5
3	0; 831
4	2; 3611
5	.5; 4156
6	-5.5; 4512
7	691; 4526
8	1148.5; 4527
9	1664.5; 4527
10	2104.5; 4527
11	2990.5; 4527
12	3622; 4525.5
13	4081.5; 4459.5
14	4081.5; 3763
15	4081.5; 3117
16	4081.5; 2279
17	4025.5; 1331
18	4029.5; 1051
19	4131.5; 285
20	3920.5; 84
21	2986.5; -70
22	2100.5; -85
23	1660.5; -85
24	1144.5; -85
25	677; -84

HV21/HV22

Pin	Function	Pin	Function	Pin	Function
1	SW2	9	SW6	17	V_{DD}
2	SW3	10	SW7	18	GND
3	SW3	11	SW7	19	V_{NN}
4	SW4	12	Data out	20	V_{PP}
5	SW4	13	N/C (CL for HV22)	21	SW0
6	SW5	14	LE	22	SW0
7	SW5	15	CK	23	SW1
8	SW6	16	DIN	24	SW1
				25	SW2

Die Specifications

	mils	mm		
Die Size:	223 X 183	5.660 X 4.640	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 LMIS
Bond Pad Size:	4.5 X 4.5	0.11 X 0.11	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		



Pad Coordinates in Microns

1	1222; 192	37	3162; 3370.5
2	1022; 62	38	3362; 3500.5
3	819; 192	39	3562.5; 3370.5
4	619; 62	40	3762.5; 3500.5
5	418.5; 192	41	3959.5; 3370.5
6	218.5; 62	42	4159.5; 3500.5
7	62.5; 240.5	43	4262; 3285.5
8	192.5; 440.5	44	4132; 3085.5
9	62; 641	45	4262; 2885
10	192; 841	46	4132; 2685
11	62; 1042	47	4262; 2484
12	192; 1242	48	4132; 2284
13	62; 1442.5	49	4262; 2083.5
14	192; 1642.5	50	4132; 1883.5
15	62; 1848.5	51	4262; 1677.5
16	192; 2048.5	52	4132; 1477.5
17	62; 2249	53	4262; 1277
18	192; 2449	54	4132; 1077
19	62; 2650	55	4262; 876
20	192; 2850	56	4132.5; 676
21	62; 3050.5	57	4262; 475.5
22	192; 3250.5	58	4266; 237.5
23	330; 3445	59	4108.5; 62
24	563.5; 3503	60	3908.5; 192
25	758.5; 3370.5	61	3709; 62
26	958.5; 3500.5	62	3509; 192
27	1159; 3370.5	63	3309; 62
28	1359; 3500.5	64	3109; 192
29	1560; 3370.5	65	2905.5; 4
30	1760; 3500.5	66	2704; 4
31	1960.5; 3370.5	67	2502.5; 4
32	2160.5; 3500.5	68	2311; 0
33	2360.5; 3370.5	69	2103; 0
34	2560.5; 3500.5	70	1901; 4
35	2761; 3370.5	71	1691; 0
36	2961; 3500.5	72	1426; 4

Die Specifications

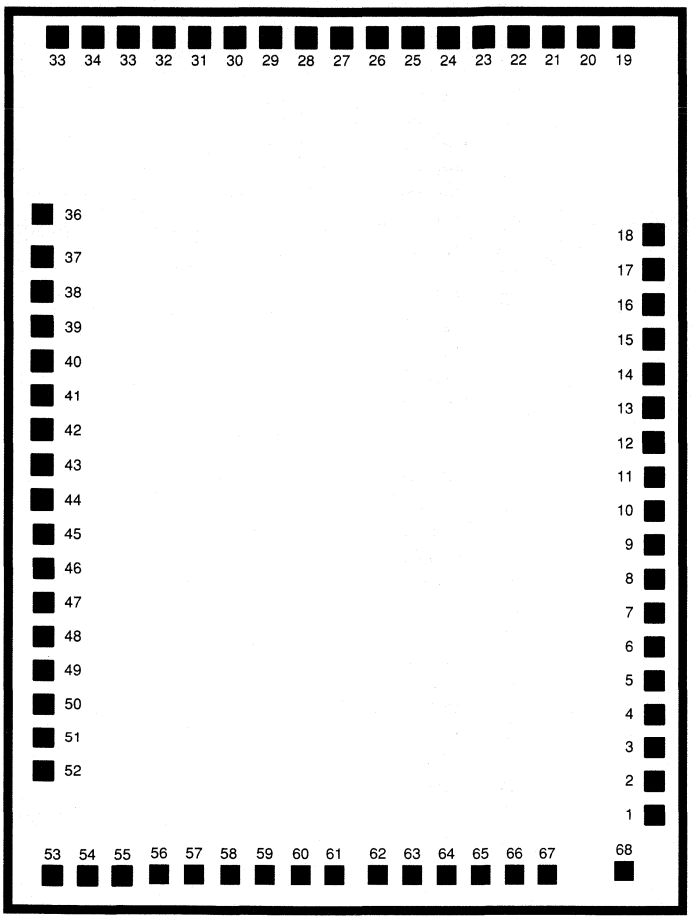
	mils	mm		
Die Size:	184 X 156	4.670 X 3.960	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 or Equal
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		

HV31

Pin	Function	Pin	Function	Pin	Function	Pin	Function
1	HV_{OUT} 1	19	HV_{OUT} 19	37	HV_{OUT} 37	55	HV_{OUT} 55
2	HV_{OUT} 2	20	HV_{OUT} 20	38	HV_{OUT} 38	56	HV_{OUT} 56
3	HV_{OUT} 3	21	HV_{OUT} 21	39	HV_{OUT} 39	57	HV_{OUT} 57
4	HV_{OUT} 4	22	HV_{OUT} 22	40	HV_{OUT} 40	58	HV_{OUT} 58
5	HV_{OUT} 5	23	HV_{OUT} 23	41	HV_{OUT} 41	59	HV_{OUT} 59
6	HV_{OUT} 6	24	HV_{OUT} 24	42	HV_{OUT} 42	60	HV_{OUT} 60
7	HV_{OUT} 7	25	HV_{OUT} 25	43	HV_{OUT} 43	61	HV_{OUT} 61
8	HV_{OUT} 8	26	HV_{OUT} 26	44	HV_{OUT} 44	62	HV_{OUT} 62
9	HV_{OUT} 9	27	HV_{OUT} 27	45	HV_{OUT} 45	63	HV_{OUT} 63
10	HV_{OUT} 10	28	HV_{OUT} 28	46	HV_{OUT} 46	64	HV_{OUT} 64
11	HV_{OUT} 11	29	HV_{OUT} 29	47	HV_{OUT} 47	65	Output Enable
12	HV_{OUT} 12	30	HV_{OUT} 30	48	HV_{OUT} 48	66	DATA IN
13	HV_{OUT} 13	31	HV_{OUT} 31	49	HV_{OUT} 49	67	LE
14	HV_{OUT} 14	32	HV_{OUT} 32	50	HV_{OUT} 50	68	V_{DD}
15	HV_{OUT} 15	33	HV_{OUT} 33	51	HV_{OUT} 51	69	GND
16	HV_{OUT} 16	34	HV_{OUT} 34	52	HV_{OUT} 52	70	CLK
17	HV_{OUT} 17	35	HV_{OUT} 35	53	HV_{OUT} 53	71	DATA OUT
18	HV_{OUT} 18	36	HV_{OUT} 36	54	HV_{OUT} 54	72	DIR

Note: HV_{OUT} sequence dependent on DIR polarity

PIN	DIR	HV_{OUT}
1	H	1
1	L	64



Pad Coordinates in Microns

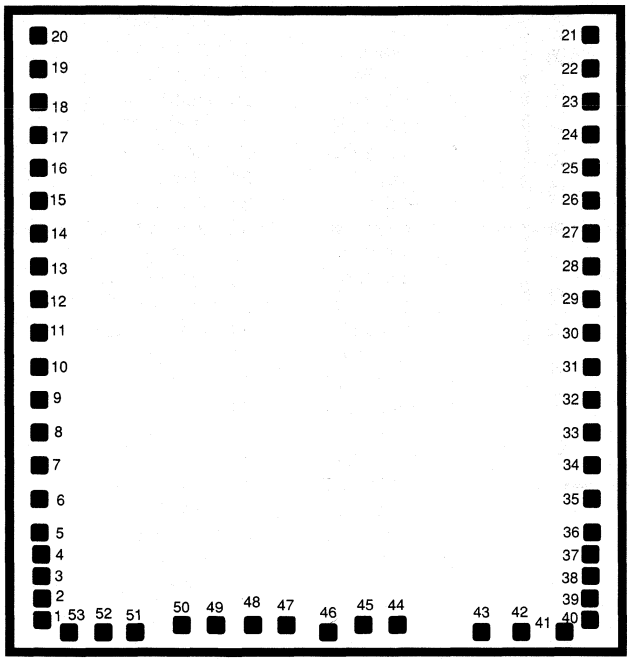
1	3118; -221	35	83; 3804
2	3118; -46	36	6; 2886.5
3	3118; 129	37	0; 2663.5
4	3118; 304	38	0; 2483.5
5	3118; 479	39	0; 2303.5
6	3118; 654	40	0; 2123.5
7	3118; 829	41	0; 1943.5
8	3118; 1004	42	0; 1763.5
9	3118; 1179	43	0; 1583.5
10	3118; 1354	44	0; 1403.5
11	3118; 1529	45	0; 1225
12	3118; 1707.5	46	0; 1050
13	3118; 1887.5	47	0; 875
14	3118; 2067.5	48	0; 700
15	3118; 2247.5	49	0; 525
16	3118; 2427.5	50	0; 350
17	3118; 2607.5	51	0; 175
18	3118; 2787.5	52	0; 0
19	2963; 3804	53	49.5; -546.5
20	2783; 3804	54	224.5; -546.5
21	2603; 3804	55	399.5; -546.5
22	2423; 3804	56	585; -529.5
23	2243; 3804	57	760; -529.5
24	2063; 3804	58	945; -529.5
25	1883; 3804	59	1120; -529.5
26	1703; 3804	60	1295; -529.5
27	1523; 3804	61	1470; -529.5
28	1343; 3804	62	1687; -529.5
29	1163; 3804	63	1862.5; -529.5
30	983; 3804	64	2037; -529.5
31	803; 3804	65	2212; -529.5
32	623; 3804	66	2387; -529.5
33	443; 3804	67	2562; -529.5
34	263; 3804	68	2952; -529.5

Die Specifications

	mils	mm		
Die Size:	137 X 185	3.470 X 4.690	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 or Equal
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		

HV33

Pin	Function	Pin	Function
1	HVS 1	35	HVD 24
2	HVS 2	36	V_{PP}
3	HVS 3	37	HVD 25
4	HVS 4	38	HVD 26
5	HVS 5	39	HVD 27
6	HVS 6	40	HVD 28
7	HVS 7	41	HVD 29
8	HVS 8	42	HVD 30
9	HVS 9	43	HVD 31
10	HVS 10	44	HVD 32
11	HVS 11	45	HVS 12
12	HVD 1	46	HVS 13
13	HVD 2	47	HVS 14
14	HVD 3	48	HVS 15
15	HVD 4	49	HVS 16
16	HVD 5	50	HVS 17
17	HVD 6	51	HVS 18
18	HVD 7	52	HVS 19
19	HVD 8	53	HVS 20
20	HVD 9	54	HVS 21
21	HVD 10	55	HVS 22
22	HVD 11	56	V_{PP}
23	HVD 12	57	NC
24	HVD 13	58	OE
25	HVD 14	59	D IN
26	HVD 15	60	V_{DD}
27	HVD 16	61	GND
28	HVD 17	62	D CK
29	HVD 18	63	D S O
30	HVD 19	64	D BK
31	HVD 20	65	S IN
32	HVD 21	66	S BLK
33	HVD 22	67	S CLK/D L
34	HVD 23	68	MODE



Pad Coordinates in Microns

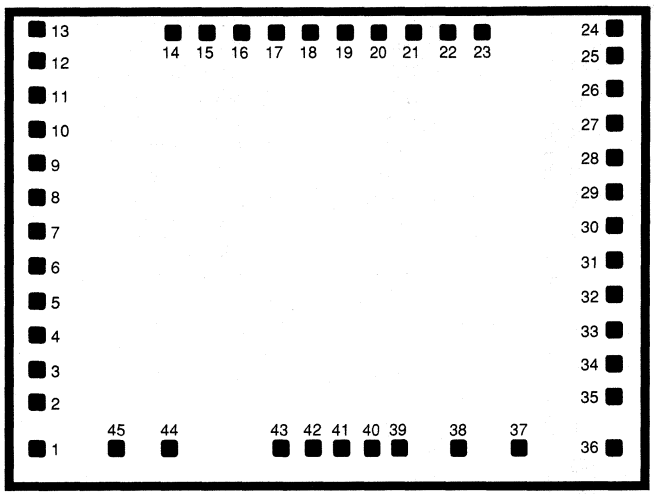
1	0; 0	27	3993; 2826.5
2	0; 158	28	3993; 2582.5
3	1; 316	29	3993; 2338.5
4	1; 474	30	3993; 2094.5
5	-9; 630.5	31	3993; 1850.5
6	-9; 874.5	32	3993; 1606.5
7	-9; 1118.5	33	3993; 1362.5
8	-9; 1362.5	34	3993; 1118.5
9	-9; 1606.5	35	3993; 874.5
10	-9; 1850.5	36	3993; 630.5
11	-6; 2094.5	37	3990; 474
12	-9; 2338.5	38	3990; 316
13	-9; 2582.5	39	3991; 158
14	-9; 2826.5	40	3991; 0
15	-9; 3070.5	41	3788; -107
16	-9; 3314.5	42	3471; -107
17	-9; 3558.5	43	3179; -107
18	-9; 3802.5	44	2578; -47
19	-9; 4046.5	45	2328; -47
20	1; 4297.5	46	2078; -107
21	3980; 4297.5	47	1770; -48
22	3980; 4297.5	48	1525; -48
23	3993; 3802.5	49	1270; -48
24	3993; 3558.5	50	1020; -48
25	3993; 3314.5	51	682; -107
26	3993; 3070.5	52	450; -107
		53	208; -107

HV38

Pin	Function	Pin	Function	Pin	Function	Pin	Function
1	HVGND	14	HV_{OUT} 7	27	HV_{OUT} 26	40	HVGND
2	V_{PP}1	15	HV_{OUT} 6	28	HV_{OUT} 25	41	Descent
3	VR	16	HV_{OUT} 5	29	HV_{OUT} 24	42	Count Clock
4	V_{PP}2	17	HV_{OUT} 4	30	HV_{OUT} 23	43	Load Count
5	HV_{OUT} 16	18	HV_{OUT} 3	31	HV_{OUT} 22	44	V_{DD}
6	HV_{OUT} 15	19	HV_{OUT} 2	32	HV_{OUT} 21	45	DIR
7	HV_{OUT} 14	20	HV_{OUT} 1	33	HV_{OUT} 20	46	LVGND
8	HV_{OUT} 13	21	HV_{OUT} 32	34	HV_{OUT} 19	47	D1
9	HV_{OUT} 12	22	HV_{OUT} 31	35	HV_{OUT} 18	48	D2
10	HV_{OUT} 11	23	HV_{OUT} 30	36	HV_{OUT} 17	49	D3
11	HV_{OUT} 10	24	HV_{OUT} 29	37	V_{PP}2	50	D4
12	HV_{OUT} 9	25	HV_{OUT} 28	38	VR	51	Shift Clock
13	HV_{OUT} 8	26	HV_{OUT} 27	39	V_{PP}1	52	N/C
						53	Ascent

Die Specifications

	mils	mm		
Die Size:	176 X 188	4.470 X 4.770	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 LMIS
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		



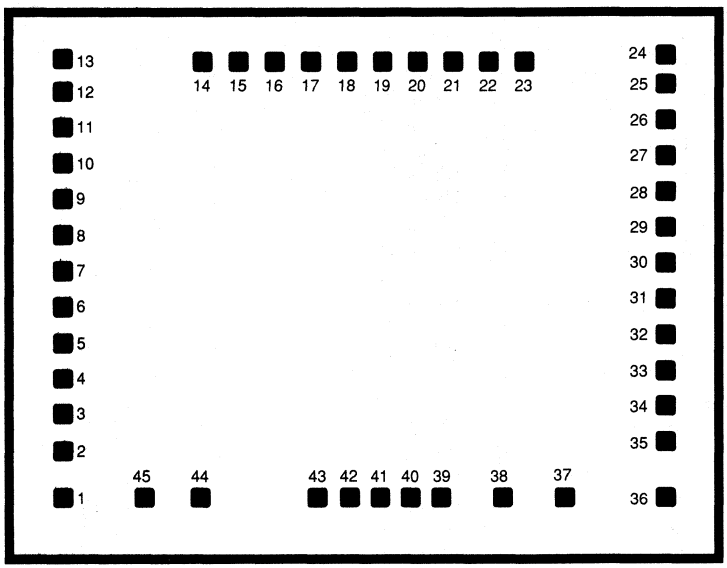
Pad Coordinates in Microns

1	0; 0	23	2990; 2827
2	-4.5; 312	24	3900.5; 2869.5
3	-4.5; 544	25	3896.5; 2682.5
4	-4.5; 776	26	3896.5; 2450.5
5	-4.5; 1008	27	3896.5; 2218.5
6	-4.5; 1240	28	3896.5; 1986.5
7	-4.5; 1472	29	3896.5; 1754.5
8	-4.5; 1704	30	3896.5; 1522.5
9	-4.5; 1936	31	3896.5; 1290.5
10	-4.5; 2168	32	3896.5; 1058.5
11	-4.5; 2400	33	3896.5; 826.5
12	-4.5; 2632	34	3896.5; 594.5
13	-6; 2846.5	35	3896.5; 362.5
14	902; 2827	36	3893.5; 8
15	1134; 2827	37	3249; 8
16	1366; 2827	38	2846; 8
17	1598; 2827	39	2443; 8
18	1830; 2827	40	2247.5; 8.5
19	2062; 2827	41	2047.5; 8.5
20	2294; 2827	42	1847.5; 8.5
21	2526; 2827	43	1639.5; 8
22	2758; 2827	44	888; 8
		45	526.5; 0

Die Specifications

	mils	mm		
Die Size:	129 X 171	3.270 X 4.340	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 LMIS
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		

HV41 Pin	HV41 Function	HV42 Pin	HV42 Function	HV45 Pin	HV45 Function	HV46 Pin	HV46 Function
1	NC	1	NC	1	NC	1	NC
2	HV_{OUT} 32	2	HV_{OUT} 1	2	HV_{OUT} 32	2	HV_{OUT} 1
3	HV_{OUT} 31	3	HV_{OUT} 2	3	HV_{OUT} 31	3	HV_{OUT} 2
4	HV_{OUT} 30	4	HV_{OUT} 3	4	HV_{OUT} 30	4	HV_{OUT} 3
5	HV_{OUT} 29	5	HV_{OUT} 4	5	HV_{OUT} 29	5	HV_{OUT} 4
6	HV_{OUT} 28	6	HV_{OUT} 5	6	HV_{OUT} 28	6	HV_{OUT} 5
7	HV_{OUT} 27	7	HV_{OUT} 6	7	HV_{OUT} 27	7	HV_{OUT} 6
8	HV_{OUT} 26	8	HV_{OUT} 7	8	HV_{OUT} 26	8	HV_{OUT} 7
9	HV_{OUT} 25	9	HV_{OUT} 8	9	HV_{OUT} 25	9	HV_{OUT} 8
10	HV_{OUT} 24	10	HV_{OUT} 9	10	HV_{OUT} 24	10	HV_{OUT} 9
11	HV_{OUT} 23	11	HV_{OUT} 10	11	HV_{OUT} 23	11	HV_{OUT} 10
12	HV_{OUT} 22	12	HV_{OUT} 11	12	HV_{OUT} 22	12	HV_{OUT} 11
13	NC	13	NC	13	NC	13	NC
14	HV_{OUT} 21	14	HV_{OUT} 12	14	HV_{OUT} 21	14	HV_{OUT} 12
15	HV_{OUT} 20	15	HV_{OUT} 13	15	HV_{OUT} 20	15	HV_{OUT} 13
16	HV_{OUT} 19	16	HV_{OUT} 14	16	HV_{OUT} 19	16	HV_{OUT} 14
17	HV_{OUT} 18	17	HV_{OUT} 15	17	HV_{OUT} 18	17	HV_{OUT} 15
18	HV_{OUT} 17	18	HV_{OUT} 16	18	HV_{OUT} 17	18	HV_{OUT} 16
19	HV_{OUT} 16	19	HV_{OUT} 17	19	HV_{OUT} 16	19	HV_{OUT} 17
20	HV_{OUT} 15	20	HV_{OUT} 18	20	HV_{OUT} 15	20	HV_{OUT} 18
21	HV_{OUT} 14	21	HV_{OUT} 19	21	HV_{OUT} 14	21	HV_{OUT} 19
22	HV_{OUT} 13	22	HV_{OUT} 20	22	HV_{OUT} 13	22	HV_{OUT} 20
23	HV_{OUT} 12	23	HV_{OUT} 21	23	HV_{OUT} 12	23	HV_{OUT} 21
24	NC	24	NC	24	NC	24	NC
25	HV_{OUT} 11	25	HV_{OUT} 22	25	HV_{OUT} 11	25	HV_{OUT} 22
26	HV_{OUT} 10	26	HV_{OUT} 23	26	HV_{OUT} 10	26	HV_{OUT} 23
27	HV_{OUT} 9	27	HV_{OUT} 24	27	HV_{OUT} 9	27	HV_{OUT} 24
28	HV_{OUT} 8	28	HV_{OUT} 25	28	HV_{OUT} 8	28	HV_{OUT} 25
29	HV_{OUT} 7	29	HV_{OUT} 26	29	HV_{OUT} 7	29	HV_{OUT} 26
30	HV_{OUT} 6	30	HV_{OUT} 27	30	HV_{OUT} 6	30	HV_{OUT} 27
31	HV_{OUT} 5	31	HV_{OUT} 28	31	HV_{OUT} 5	31	HV_{OUT} 28
32	HV_{OUT} 4	32	HV_{OUT} 29	32	HV_{OUT} 4	32	HV_{OUT} 29
33	HV_{OUT} 3	33	HV_{OUT} 30	33	HV_{OUT} 3	33	HV_{OUT} 30
34	HV_{OUT} 2	34	HV_{OUT} 31	34	HV_{OUT} 2	34	HV_{OUT} 31
35	HV_{OUT} 1	35	HV_{OUT} 32	35	HV_{OUT} 1	35	HV_{OUT} 32
36	NC	36	NC	36	NC	36	NC
37	Data In	37	Data In	37	Blanking	37	Blanking
38	Strobe	38	Strobe	38	Data In	38	Data In
39	NC	39	NC	39	LE	39	LE
40	V_{DD}	40	V_{DD}	40	V_{DD}	40	V_{DD}
41	GND	41	GND	41	GND	41	GND
42	GND	42	GND	42	GND	42	GND
43	Clock	43	Clock	43	Clock	43	Clock
44	Output Enable	44	Output Enable	44	Polarity	44	Polarity
45	Data Out	45	Data Out	45	D_{OUT}	45	D_{OUT}



Pad Coordinates in Microns

1	0; 0	23	2990; 2827
2	-4.5; 312	24	3900.5; 2869.5
3	-4.5; 544	25	3896.5; 2682.5
4	-4.5; 776	26	3896.5; 2450.5
5	-4.5; 1008	27	3896.5; 2218.5
6	-4.5; 1240	28	3896.5; 1986.5
7	-4.5; 1472	29	3896.5; 1754.5
8	-4.5; 1704	30	3896.5; 1522.5
9	-4.5; 1936	31	3896.5; 1290.5
10	-4.5; 2168	32	3896.5; 1058.5
11	-4.5; 2400	33	3896.5; 826.5
12	-4.5; 2632	34	3896.5; 594.5
13	-6; 2846.5	35	3896.5; 362.5
14	902; 2827	36	3093.5; 8
15	1134; 2827	37	3249; 8
16	1366; 2827	38	2846; 8
17	1598; 2827	39	2443; 8
18	1830; 2827	40	2247.5; 8.5
19	2062; 2827	41	2047.5; 8.5
20	2294; 2827	42	1847.5; 8.5
21	2526; 2827	43	1639.5; 8
22	2758; 2827	44	888; 8
		45	526.5; 0

Die Specifications

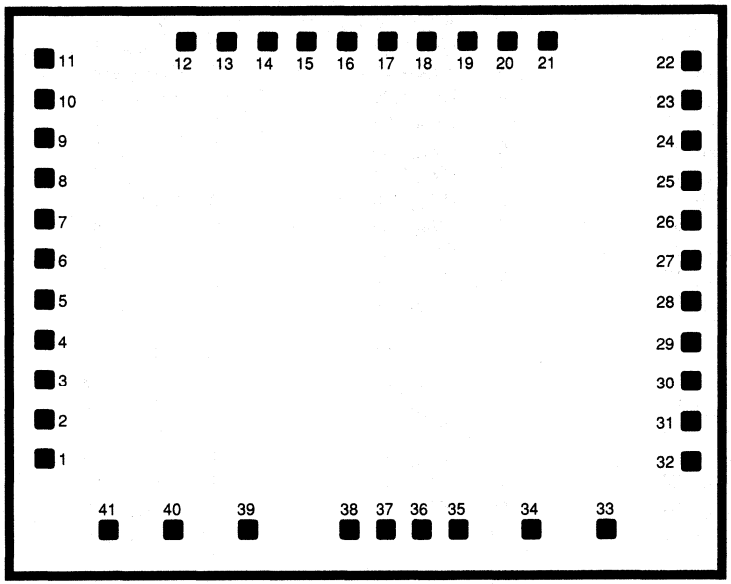
	mils	mm		
Die Size:	129 X 171	3.270 X 4.340	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 LMIS
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		

HV51	
Pin	**Function**
1	GND
2	HV_{OUT} 32
3	HV_{OUT} 31
4	HV_{OUT} 30
5	HV_{OUT} 29
6	HV_{OUT} 28
7	HV_{OUT} 27
8	HV_{OUT} 26
9	HV_{OUT} 25
10	HV_{OUT} 24
11	HV_{OUT} 23
12	HV_{OUT} 22
13	GND
14	HV_{OUT} 21
15	HV_{OUT} 20
16	HV_{OUT} 19
17	HV_{OUT} 18
18	HV_{OUT} 17
19	HV_{OUT} 16
20	HV_{OUT} 15
21	HV_{OUT} 14
22	HV_{OUT} 13
23	HV_{OUT} 12
24	GND
25	HV_{OUT} 11
26	HV_{OUT} 10
27	HV_{OUT} 9
28	HV_{OUT} 8
29	HV_{OUT} 7
30	HV_{OUT} 6
31	HV_{OUT} 5
32	HV_{OUT} 4
33	HV_{OUT} 3
34	HV_{OUT} 2
35	HV_{OUT} 1
36	GND
37	Data In
38	Strobe
39	NC
40	V_{DD}
41	GND
42	GND
43	Clock
44	Output Enable
45	Data Out

HV52	
Pin	**Function**
1	GND
2	HV_{OUT} 1
3	HV_{OUT} 2
4	HV_{OUT} 3
5	HV_{OUT} 4
6	HV_{OUT} 5
7	HV_{OUT} 6
8	HV_{OUT} 7
9	HV_{OUT} 8
10	HV_{OUT} 9
11	HV_{OUT} 10
12	HV_{OUT} 11
13	GND
14	HV_{OUT} 12
15	HV_{OUT} 13
16	HV_{OUT} 14
17	HV_{OUT} 15
18	HV_{OUT} 16
19	HV_{OUT} 17
20	HV_{OUT} 18
21	HV_{OUT} 19
22	HV_{OUT} 20
23	HV_{OUT} 21
24	GND
25	HV_{OUT} 22
26	HV_{OUT} 23
27	HV_{OUT} 24
28	HV_{OUT} 25
29	HV_{OUT} 26
30	HV_{OUT} 27
31	HV_{OUT} 28
32	HV_{OUT} 29
33	HV_{OUT} 30
34	HV_{OUT} 31
35	HV_{OUT} 32
36	GND
37	Data In
38	Strobe
39	NC
40	V_{DD}
41	GND
42	GND
43	Clock
44	Output Enable
45	Data Out

HV55	
Pin	**Function**
1	V_{SS}
2	HV_{OUT} 32
3	HV_{OUT} 31
4	HV_{OUT} 30
5	HV_{OUT} 29
6	HV_{OUT} 28
7	HV_{OUT} 27
8	HV_{OUT} 26
9	HV_{OUT} 25
10	HV_{OUT} 24
11	HV_{OUT} 23
12	HV_{OUT} 22
13	V_{SS}
14	HV_{OUT} 21
15	HV_{OUT} 20
16	HV_{OUT} 19
17	HV_{OUT} 18
18	HV_{OUT} 17
19	HV_{OUT} 16
20	HV_{OUT} 15
21	HV_{OUT} 14
22	HV_{OUT} 13
23	HV_{OUT} 12
24	V_{SS}
25	HV_{OUT} 11
26	HV_{OUT} 10
27	HV_{OUT} 9
28	HV_{OUT} 8
29	HV_{OUT} 7
30	HV_{OUT} 6
31	HV_{OUT} 5
32	HV_{OUT} 4
33	HV_{OUT} 3
34	HV_{OUT} 2
35	HV_{OUT} 1
36	V_{SS}
37	Blanking
38	Data In
39	Latch Enable
40	V_{DD}
41	V_{SS}
42	V_{SS}
43	Clock
44	Polarity
45	Data Out

HV56	
Pin	**Function**
1	V_{SS}
2	HV_{OUT} 1
3	HV_{OUT} 2
4	HV_{OUT} 3
5	HV_{OUT} 4
6	HV_{OUT} 5
7	HV_{OUT} 6
8	HV_{OUT} 7
9	HV_{OUT} 8
10	HV_{OUT} 9
11	HV_{OUT} 10
12	HV_{OUT} 11
13	V_{SS}
14	HV_{OUT} 12
15	HV_{OUT} 13
16	HV_{OUT} 14
17	HV_{OUT} 15
18	HV_{OUT} 16
19	HV_{OUT} 17
20	HV_{OUT} 18
21	HV_{OUT} 19
22	HV_{OUT} 20
23	HV_{OUT} 21
24	V_{SS}
25	HV_{OUT} 22
26	HV_{OUT} 23
27	HV_{OUT} 24
28	HV_{OUT} 25
29	HV_{OUT} 26
30	HV_{OUT} 27
31	HV_{OUT} 28
32	HV_{OUT} 29
33	HV_{OUT} 30
34	HV_{OUT} 31
35	HV_{OUT} 32
36	V_{SS}
37	Blanking
38	Data In
39	Latch Enable
40	V_{DD}
41	V_{SS}
42	V_{SS}
43	Clock
44	Polarity
45	Data Out



Pad Coordinates in Microns

1	0; 0	21	2750.5; 2312
2	0; 220	22	3522.5; 2200.5
3	0; 440	23	3522.5; 1980.5
4	0; 660	24	3522.5; 1760.5
5	0; 880	25	3522.5; 1540.5
6	0; 1100	26	3522.5; 1320.5
7	0; 1320	27	3522.5; 1100.5
8	0; 1540	28	3522.5; 880.5
9	0; 1760	29	3522.5; 660.5
10	0; 1980	30	3522.5; 440.5
11	0; 2200	31	3522.5; 220.5
12	770.5; 2312	32	3522.5; 0.5
13	990.5; 2312	33	3069.25; -390.75
14	1210.5; 2312	34	2666.75; -390.75
15	1430.5; 2312	35	2263.75; -390.75
16	1650.5; 2312	36	2062.75; -390.75
17	1870.5; 2312	37	1862.75; -390.75
18	1870.5; 2312	38	1662.75; -390.75
19	2310.5; 2312	39	1110.75; 390.75
20	2530.5; 2312	40	708.25; 390.75
		41	346.75; 390.75

Die Specifications

	mils	mm		
Die Size:	155 X 125	3.930 X 3.170	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 or Equal
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		

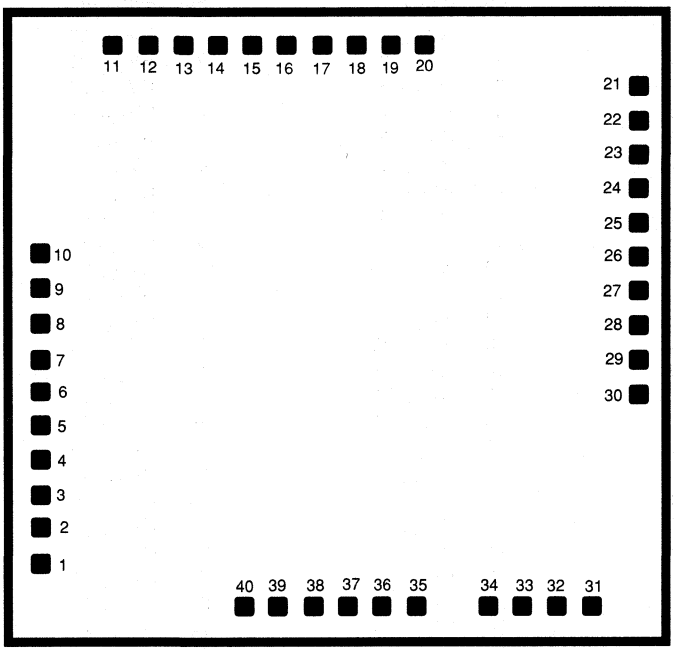
Backside is V_{PP}

HV53	
Pin	**Function**
1	HV_{OUT} 1
2	HV_{OUT} 2
3	HV_{OUT} 3
4	HV_{OUT} 4
5	HV_{OUT} 5
6	HV_{OUT} 6
7	HV_{OUT} 7
8	HV_{OUT} 8
9	HV_{OUT} 9
10	HV_{OUT} 10
11	HV_{OUT} 11
12	HV_{OUT} 12
13	HV_{OUT} 13
14	HV_{OUT} 14
15	HV_{OUT} 15
16	HV_{OUT} 16
17	HV_{OUT} 17
18	HV_{OUT} 18
19	HV_{OUT} 19
20	HV_{OUT} 20
21	HV_{OUT} 21
22	HV_{OUT} 22
23	HV_{OUT} 23
24	HV_{OUT} 24
25	HV_{OUT} 25
26	HV_{OUT} 26
27	HV_{OUT} 27
28	HV_{OUT} 28
29	HV_{OUT} 29
30	HV_{OUT} 30
31	HV_{OUT} 31
32	HV_{OUT} 32
33	OE
34	Data In
35	LE
36	V_{DD}
37	V_{PP}
38	V_{SS}
39	CLK
40	NC
41	Data Out

HV54	
Pin	**Function**
1	HV_{OUT} 32
2	HV_{OUT} 31
3	HV_{OUT} 30
4	HV_{OUT} 29
5	HV_{OUT} 28
6	HV_{OUT} 27
7	HV_{OUT} 26
8	HV_{OUT} 25
9	HV_{OUT} 24
10	HV_{OUT} 23
11	HV_{OUT} 22
12	HV_{OUT} 21
13	HV_{OUT} 20
14	HV_{OUT} 19
15	HV_{OUT} 18
16	HV_{OUT} 17
17	HV_{OUT} 16
18	HV_{OUT} 15
19	HV_{OUT} 14
20	HV_{OUT} 13
21	HV_{OUT} 12
22	HV_{OUT} 11
23	HV_{OUT} 10
24	HV_{OUT} 9
25	HV_{OUT} 8
26	HV_{OUT} 7
27	HV_{OUT} 6
28	HV_{OUT} 5
29	HV_{OUT} 4
30	HV_{OUT} 3
31	HV_{OUT} 2
32	HV_{OUT} 1
33	OE
34	Data In
35	LE
36	V_{DD}
37	V_{PP}
38	V_{SS}
39	CLK
40	NC
41	Data Out

HV57	
Pin	**Function**
1	HV_{OUT} 1
2	HV_{OUT} 2
3	HV_{OUT} 3
4	HV_{OUT} 4
5	HV_{OUT} 5
6	HV_{OUT} 6
7	HV_{OUT} 7
8	HV_{OUT} 8
9	HV_{OUT} 9
10	HV_{OUT} 10
11	HV_{OUT} 11
12	HV_{OUT} 12
13	HV_{OUT} 13
14	HV_{OUT} 14
15	HV_{OUT} 15
16	HV_{OUT} 16
17	HV_{OUT} 17
18	HV_{OUT} 18
19	HV_{OUT} 19
20	HV_{OUT} 20
21	HV_{OUT} 21
22	HV_{OUT} 22
23	HV_{OUT} 23
24	HV_{OUT} 24
25	HV_{OUT} 25
26	HV_{OUT} 26
27	HV_{OUT} 27
28	HV_{OUT} 28
29	HV_{OUT} 29
30	HV_{OUT} 30
31	HV_{OUT} 31
32	HV_{OUT} 32
33	Blanking
34	Data In
35	Latch Enable
36	V_{DD}
37	V_{PP}
38	V_{SS}
39	CLK
40	Polarity
41	Data Out

HV58	
Pin	**Function**
1	HV_{OUT} 32
2	HV_{OUT} 31
3	HV_{OUT} 30
4	HV_{OUT} 29
5	HV_{OUT} 28
6	HV_{OUT} 27
7	HV_{OUT} 26
8	HV_{OUT} 25
9	HV_{OUT} 24
10	HV_{OUT} 23
11	HV_{OUT} 22
12	HV_{OUT} 21
13	HV_{OUT} 20
14	HV_{OUT} 19
15	HV_{OUT} 18
16	HV_{OUT} 17
17	HV_{OUT} 16
18	HV_{OUT} 15
19	HV_{OUT} 14
20	HV_{OUT} 13
21	HV_{OUT} 12
22	HV_{OUT} 11
23	HV_{OUT} 10
24	HV_{OUT} 9
25	HV_{OUT} 8
26	HV_{OUT} 7
27	HV_{OUT} 6
28	HV_{OUT} 5
29	HV_{OUT} 4
30	HV_{OUT} 3
31	HV_{OUT} 2
32	HV_{OUT} 1
33	Blanking
34	Data In
35	Latch Enable
36	V_{DD}
37	V_{PP}
38	V_{SS}
39	CLK
40	Polarity
41	Data Out



Pad Coordinates in Microns

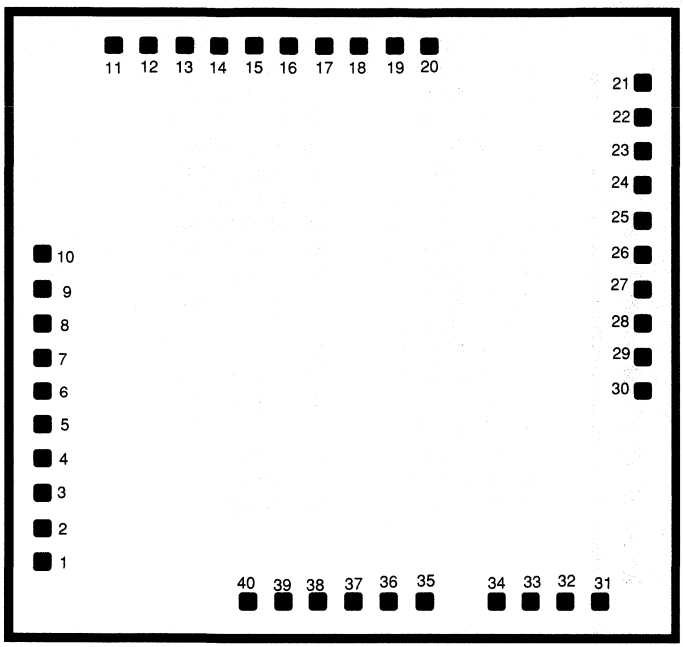
1	0; 0	21	3451; 2816
2	0; 200	22	3451; 2616
3	0; 400	23	3451; 2416
4	0; 600	24	3451; 2216
5	0; 800	25	3451; 2016
6	0; 1000	26	3451; 1816
7	0; 1200	27	3451; 1616
8	0; 1400	28	3451; 1416
9	0; 1600	29	3451; 1216
10	0; 1800	30	3451; 1016
11	406; 3030	31	3195; -228
12	606; 3030	32	2995; -228
13	806; 3030	33	2795; -228
14	1006; 3030	34	2595; -228
15	1206; 3030	35	2174; -228
16	1406; 3030	36	1974; -228
17	1606; 3030	37	1774; -228
18	1806; 3030	38	1574; -228
19	2006; 3030	39	1374; -228
20	2206; 3030	40	1174; -228

HV500

Pin	Function	Pin	Function	Pin	Function	Pin	Function
1	4Q1	11	3Q3	21	2Q6	31	1Q4
2	4Q2	12	3Q4	22	2Q5	32	1Q3
3	4Q3	13	3Q5	23	2Q4	33	1Q2
4	4Q4	14	3Q6	24	2Q3	34	1Q1
5	4Q5	15	3Q7	25	2Q2	35	Clock
6	4Q6	16	3Q8	26	2Q1	36	Data In
7	4Q7	17	V_{PP}	27	1Q8	37	Select
8	4Q8	18	GND	28	1Q7	38	V_{DD}
9	3Q1	19	2Q8	29	1Q6	39	Select 1
10	3Q2	20	2Q7	30	1Q5	40	Strobe

Die Specifications

	mils	mm		
Die Size:	153 X 146	3.880 X 0.700	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 LMIS
Bond Pad Size:	4.5 X 4.5	0.11 X 0.11	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		



Pad Coordinates in Microns

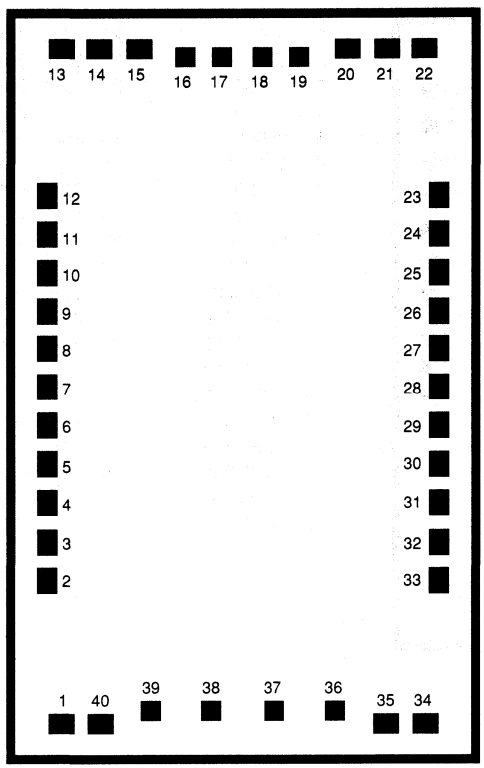
1	0; 0	21	3451; 2816
2	0; 200	22	3451; 2616
3	0; 400	23	3451; 2416
4	0; 600	24	3451; 2216
5	0; 800	25	3451; 2016
6	0; 1000	26	3451; 1816
7	0; 1200	27	3451; 1616
8	0; 1400	28	3451; 1416
9	0; 1600	29	3051; 1216
10	0; 1800	30	3051; 1016
11	406; 3030	31	3195; -228
12	606; 3030	32	2995; -228
13	806; 3030	33	2795; -228
14	1006; 3030	34	2595; -228
15	1206; 3030	35	1974; -228
16	1406; 3030	36	1974; -228
17	1606; 3030	37	1774; -228
18	1806; 3030	38	1574; -228
19	2006; 3030	39	1374; -228
20	2206; 3030	40	1174; -228

HV501

Pin	Function	Pin	Function	Pin	Function	Pin	Function
1	HV_{OUT} 32	12	HV_{OUT} 21	22	HV_{OUT} 13	32	HV_{OUT} 3
2	HV_{OUT} 31	13	HV_{OUT} 20	23	HV_{OUT} 12	33	HV_{OUT} 2
3	HV_{OUT} 30	14	HV_{OUT} 19	24	HV_{OUT} 11	34	HV_{OUT} 1
4	HV_{OUT} 29	15	HV_{OUT} 18	25	HV_{OUT} 10	35	Strobe
6	HV_{OUT} 27	16	HV_{OUT} 17	26	HV_{OUT} 9	36	Sustain
7	HV_{OUT} 26	17	V_{PP}	27	HV_{OUT} 8	37	Clock
8	HV_{OUT} 25	18	GND	28	HV_{OUT} 7	38	V_{DD}
9	HV_{OUT} 24	19	HV_{OUT} 16	29	HV_{OUT} 6	39	Data in
10	HV_{OUT} 23	20	HV_{OUT} 15	30	HV_{OUT} 5	40	Data out
11	HV_{OUT} 22	21	HV_{OUT} 14	31	HV_{OUT} 4		

Die Specifications

	mils	mm		
Die Size:	153 X 146	3.880 X 3.700	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 LMIS
Bond Pad Size:	4.5 X 4.5	0.11 X 0.11	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		



Pad Coordinates in Microns

1	0; 0	21	1770; 3698
2	-77; 796	22	1978; 3698
3	-77; 1004	23	2056.5; 2891
4	-77; 1215	24	2056.5; 2680
5	-77; 1423	25	2056.5; 2472
6	-77; 1634	26	2056.5; 2261
7	-77; 1842	27	2056.5; 2053
8	-77; 2053	28	2056.5; 1842
9	-77; 2261	29	2056.5; 1634
10	-77; 2472	30	2056.5; 1423
11	-77; 2680	31	2056.5; 1215
12	-77; 2891	32	2056.5; 1004
13	1.5; 3698	33	2056.5; 796
14	209.5; 3698	34	1979.5; 0
15	420.5; 3698	35	1768.5; 0
16	668; 3658	36	-1484.5; 78
17	868; 3658	37	1148.5; 78
18	1088; 3658	38	812.5; 78
19	1288; 3658	39	476.5; 78
20	1559; 3698	40	211; 0

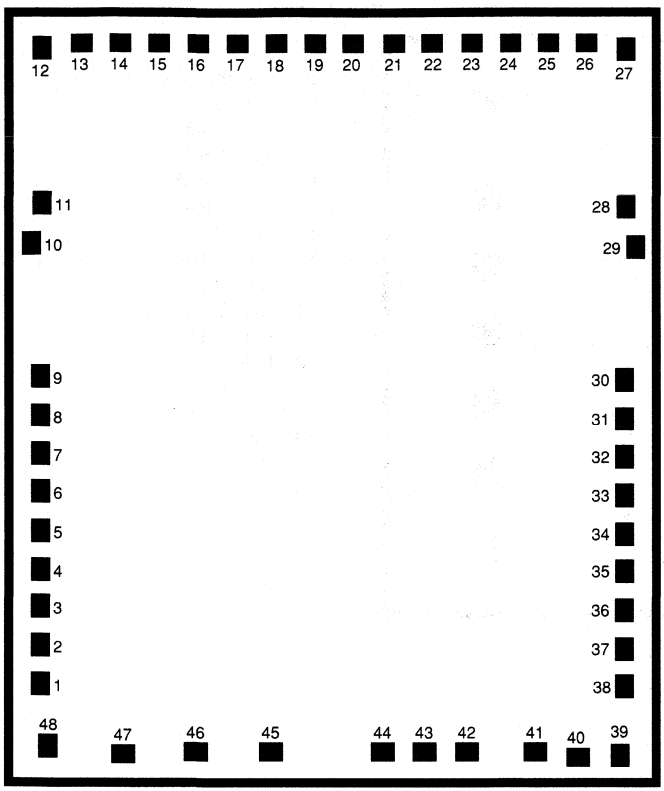
HV518

Pin	Function	Pin	Function	Pin	Function	Pin	Function
1	HV_{OUT} 18	11	HV_{OUT} 28	21	HV_{OUT} 2	31	HV_{OUT} 12
2	HV_{OUT} 19	12	HV_{OUT} 29	22	HV_{OUT} 3	32	HV_{OUT} 13
3	HV_{OUT} 20	13	HV_{OUT} 30	23	HV_{OUT} 4	33	HV_{OUT} 14
4	HV_{OUT} 21	14	HV_{OUT} 31	24	HV_{OUT} 5	34	HV_{OUT} 15
5	HV_{OUT} 22	15	HV_{OUT} 32	25	HV_{OUT} 6	35	HV_{OUT} 16
6	HV_{OUT} 23	16	Serial out	26	HV_{OUT} 7	36	Latch Enable
7	HV_{OUT} 24	17	V_{PP}	27	HV_{OUT} 8	37	Clock
8	HV_{OUT} 25	18	V_{DD}	28	HV_{OUT} 9	38	GND
9	HV_{OUT} 26	19	Data In	29	HV_{OUT} 10	39	Strobe
10	HV_{OUT} 27	20	HV_{OUT} 1	30	HV_{OUT} 11	40	HV_{OUT} 17

Die Specifications

	mils	mm		
Die Size:	101 X 163	2.560 X 4.140	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 or equal
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		

Backside is V_{PP}



Pad Coordinates in Microns

1	-53.5; 450	25	3593; 5142.5
2	-53.5; 730	26	3872; 5142.5
3	-53.5; 1010	27	4148.5; 5109.5
4	-53.5; 1290	28	4154.4; 3952
5	-53.5; 1570	29	4218; 3662
6	053; 1850	30	4146.5; 2690
7	-53.5; 2130	31	4146.5; 2409
8	-53.5; 2410	32	4146.5; 2130
9	-53.5; 2690	33	4146.5; 1849
10	-120; 3676.5	34	4146.5; 1570
11	-45; 3966	35	4146.5; 1289
12	-45; 3966	36	4146.5; 1010
13	223; 5142.5	37	4146.5; 729
14	512; 5142.5	38	4146.5; 450
15	793; 5142.5	39	4092.5; -30
16	1072; 5142.5	40	3801; -70.5
17	1353; 5142.5	41	3491; -32.5
18	1632; 5142.5	42	3007; -32.5
19	1913; 5142.5	43	2702; -32.5
20	2192; 5142.5	44	2392; -32.5
21	2473; 5142.5	45	1599; -32.5
22	2752; 5142.5	46	1060; -32.5
23	3033; 5142.5	47	537.5; -61
24	3312; 5142.5	48	0; 0

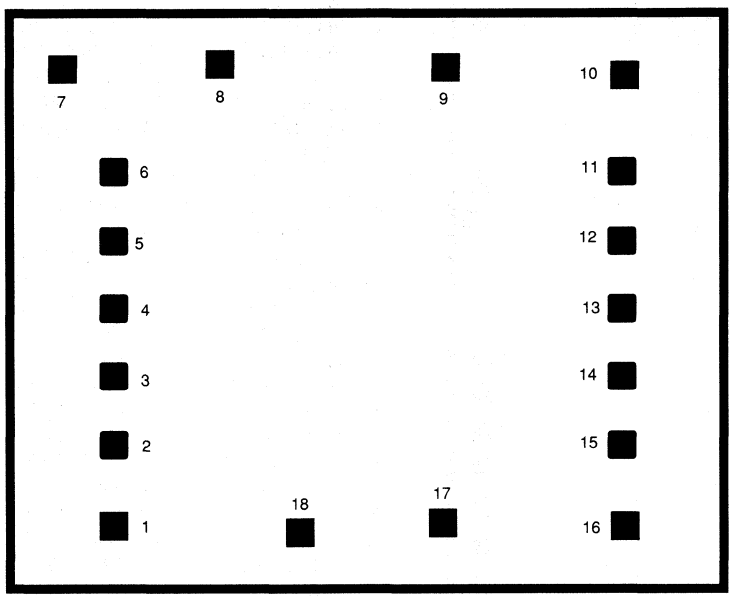
HV60

Pin	Function	Pin	Function	Pin	Function	Pin	Function	Pin	Function
1	HV_{OUT} 1	11	V_{NN}	21	HV_{OUT} 18	31	HV_{OUT} 25	41	V_{DD}(2)+5
2	HV_{OUT} 2	12	GND	22	HV_{OUT} 19	32	HV_{OUT} 26	42	ENABLE
3	HV_{OUT} 3	13	HV_{OUT} 10	23	HV_{OUT} 20	33	HV_{OUT} 27	43	V_{DD}(1)-5
4	HV_{OUT} 4	14	HV_{OUT} 11	24	HV_{OUT} 21	34	HV_{OUT} 28	44	$\overline{\text{CLEAR}}$
5	HV_{OUT} 5	15	HV_{OUT} 12	25	HV_{OUT} 22	35	HV_{OUT} 29	45	CLOCK
6	HV_{OUT} 6	16	HV_{OUT} 13	26	HV_{OUT} 23	36	HV_{OUT} 30	46	PHASE SHIFT
7	HV_{OUT} 7	17	HV_{OUT} 14	27	GND	37	HV_{OUT} 31	47	GND
8	HV_{OUT} 8	18	HV_{OUT} 15	28	V_{NN}	38	HV_{OUT} 32	48	DATA IN
9	HV_{OUT} 9	19	HV_{OUT} 16	29	V_{PP}	39	DATA OUT		
10	V_{PP}	20	HV_{OUT} 17	30	HV_{OUT} 24	40	GND		

Die Specifications

	mils	mm		
Die Size:	184 X 224	4.670 X 5.680	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 or equal
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		

Back side is GND



Pad Coordinates in Microns

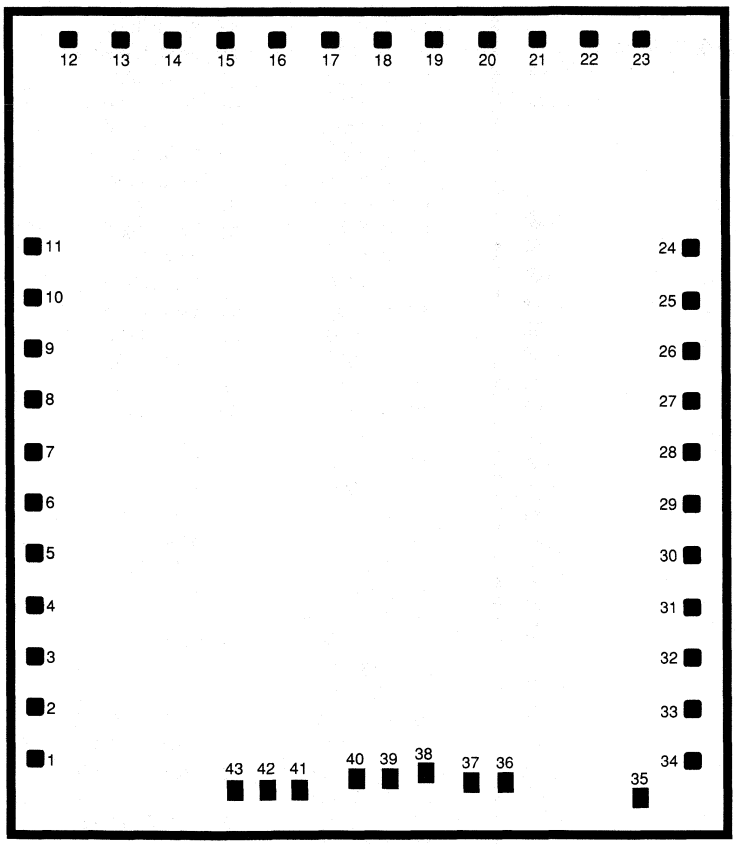
1	0; 0
2	-4.5; 262.5
3	-4.5; 483.5
4	-4.5; 704.5
5	-4.5; 925.5
6	-4.5; 1146.5
7	-161; 1484
8	347; 1499
9	1069; 1484
10	1646; 1466
11	1640.5; 1146.5
12	1640.5; 925.5
13	1640.5; 704.5
14	1640.5; 483.5
15	1640.5; 262.5
16	1650; 0
17	1069; 14
18	599; -18

HV6810

Pin	Function	Pin	Function
1	Clock	10	Blanking
2	Q6	11	Q1
3	Q7	12	Q2
4	Q8	13	Q3
5	Q9	14	Q4
6	Q10	15	Q5
7	Serial Data out	16	STB
8	V_{BB}	17	V_{DD}
9	Serial Data out	18	V_{SS}

Die Specifications

	mils	mm		
Die Size:	76 X 93	1.930 X 2.360	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 LMIS
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		



Pad Coordinates in Microns

1	0; 0	23	3307.5; 3983
2	0; 283	24	3576.5; 2830
3	0; 566	25	3576.5; 2547
4	0; 849	26	3576.5; 2264
5	0; 1132	27	3576.5; 1981
6	0; 1415	28	3576.5; 1698
7	0; 1698	29	3576.5; 1415
8	0; 1981	30	3576.5; 1132
9	0; 2264	31	3576.5; 849
10	0; 2547	32	3576.5; 566
11	0; 2830	33	3576.5; 283
12	194.5; 3983	34	3576.5; 0
13	477.5; 3983	35	3282.5; -204
14	760.5; 3983	36	2544; -127
15	1043.5; 3983	37	2354; -127
16	1326.5; 3983	38	2104.5; -83.5
17	1609.5; 3983	39	1914.5; -111
18	1892.5; 3983	40	1729; -111
19	2175.5; 3983	41	1424.5; -166.5
20	2458.5; 3983	42	1249.5; -166.5
21	2741.5; 3983	43	1074.5; -166.5
22	3024.5; 3983		

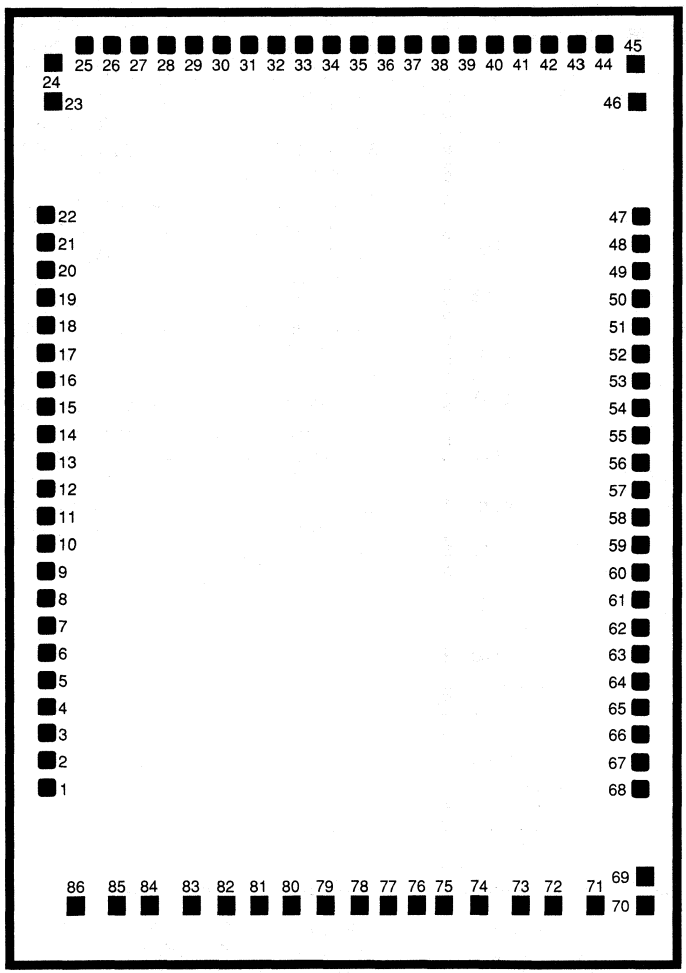
HV70[1]

Pin	Function	Pin	Function	Pin	Function	Pin	Function	Pin	Function	Pin	Function
1	HV_{OUT}	8	HV_{OUT}	15	HV_{OUT}	22	HV_{OUT}	29	HV_{OUT}	36	Data In
2	HV_{OUT}	9	HV_{OUT}	16	HV_{OUT}	23	HV_{OUT}	30	HV_{OUT}	37	POL
3	HV_{OUT}	10	HV_{OUT}	17	HV_{OUT}	24	HV_{OUT}	31	HV_{OUT}	38	V_{DD}
4	HV_{OUT}	11	HV_{OUT}	18	HV_{OUT}	25	HV_{OUT}	32	HV_{OUT}	39	DIR
5	HV_{OUT}	12	HV_{OUT}	19	HV_{OUT}	26	HV_{OUT}	33	HV_{OUT}	40	GND
6	HV_{OUT}	13	HV_{OUT}	20	HV_{OUT}	27	HV_{OUT}	34	HV_{OUT}	41	CLK
7	HV_{OUT}	14	HV_{OUT}	21	HV_{OUT}	28	HV_{OUT}	35	V_{PP}	42	OE
										43	Data Out

Die Specifications

	mils	mm		
Die Size:	155 X 180	3.930 X 4.570	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Ablestick 84-1 or equal
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		

1 DIR = H PIN 1 = HV_{OUT}1; DIR = L PIN 1 = HV_{OUT} 34
2 Backside is V_{PP}



Notes:
1 HV_{OUT} location is dependent on DIR pin. The label above is for DIR high.
2 Backside is V_{PP}
3 For I_{PP} > 1.5A use pads 23, 46 for GND and pads 24, 45 for V_{PP}

Pad Coordinates in Microns

1	0; 0	44	3253; 4367
2	0; 160	45	3431.5; 4249.5
3	0; 320	46	3436; 4024
4	0; 480	47	3466; 3360
5	0; 640	48	3466; 3200
6	0; 800	49	3466; 3040
7	0; 960	50	3466; 2880
8	0; 1120	51	3466; 2720
9	0; 1280	52	3466; 2560
10	0; 1440	53	3466; 2400
11	0; 1600	54	3466; 2240
12	0; 1760	55	3466; 2080
13	0; 1920	56	3466; 1920
14	0; 2080	57	3466; 1760
15	0; 2240	58	3466; 1600
16	0; 2400	59	3466; 1440
17	0; 2560	60	3466; 1280
18	0; 2720	61	3466; 1120
19	0; 2880	62	3466; 960
20	0; 3040	63	3466; 800
21	0; 3200	64	3466; 640
22	0; 3360	65	3466; 480
23	30; 4024	66	3466; 320
24	34.5; 4249.5	67	3466; 160
25	213; 4367	68	3466; 0
26	373; 4367	69	3497.5; -509.5
27	533; 4367	70	3497.5; -684.5
28	693; 4367	71	3208.5; - 693.5
29	853; 4367	72	2966.5; -693.5
30	1013; 4367	73	2768.5; -693.5
31	1173; 4367	74	2526.5; -693.5
32	1333; 4367	75	2324.5; -693.5
33	1493; 4367	76	2161; -693.5
34	1653; 4367	77	1986; -693.5
35	1813; 4367	78	1823.5; -693.5
36	1873; 4367	79	1624; -693.5
37	2133; 4367	80	1424.5; -693.5
38	2233; 4367	81	1235.5; -693.5
39	2453; 4367	82	1044.5; -693.5
40	2613; 4367	83	842.5; -693.5
41	2773; 4367	84	600.5; - 693.5
42	2933; 4367	85	402.5; -693.5
43	3033; 4367	86	160.5; -693.5

Die Specifications

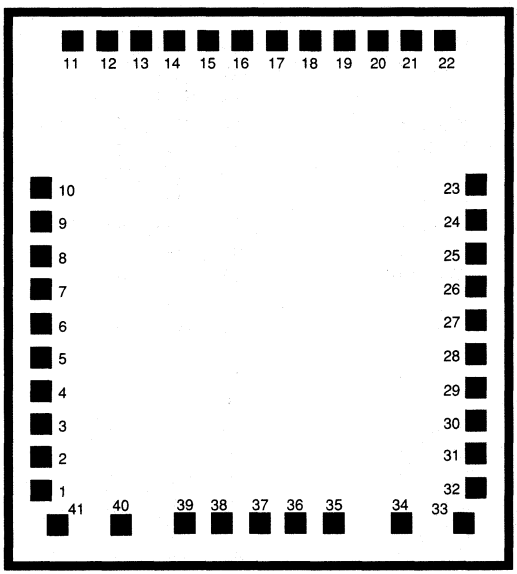
	mils	mm		
Die Size:	155 X 222	3.930 X 5.630	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 or equal
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		

HV77

Pin	Function	Pin	Function
1	HV_{OUT} 1	44	HV_{OUT} 42
2	HV_{OUT} 2	45	V_{PP}
3	HV_{OUT} 3	46	GND
4	HV_{OUT} 4	47	HV_{OUT} 43
5	HV_{OUT} 5	48	HV_{OUT} 44
6	HV_{OUT} 6	49	HV_{OUT} 45
7	HV_{OUT} 7	50	HV_{OUT} 46
8	HV_{OUT} 8	51	HV_{OUT} 47
9	HV_{OUT} 9	52	HV_{OUT} 48
10	HV_{OUT} 10	53	HV_{OUT} 49
11	HV_{OUT} 11	54	HV_{OUT} 50
12	HV_{OUT} 12	55	HV_{OUT} 51
13	HV_{OUT} 13	56	HV_{OUT} 52
14	HV_{OUT} 14	57	HV_{OUT} 53
15	HV_{OUT} 15	58	HV_{OUT} 54
16	HV_{OUT} 16	59	HV_{OUT} 55
17	HV_{OUT} 17	60	HV_{OUT} 56
18	HV_{OUT} 18	61	HV_{OUT} 57
19	HV_{OUT} 19	62	HV_{OUT} 58
20	HV_{OUT} 20	63	HV_{OUT} 59
21	HV_{OUT} 21	64	HV_{OUT} 60
22	HV_{OUT} 22	65	HV_{OUT} 61
23	GND	66	HV_{OUT} 62
24	V_{PP}	67	HV_{OUT} 63
25	HV_{OUT} 23	68	HV_{OUT} 64
26	HV_{OUT} 24	69	V_{PP}
27	HV_{OUT} 25	70	V_{PP}
28	HV_{OUT} 26	71	Data In/Out B
29	HV_{OUT} 27	72	Data In/Out B
30	HV_{OUT} 28	73	Data In/Out B
31	HV_{OUT} 29	74	Data In/Out B
32	HV_{OUT} 30	75	POL
33	HV_{OUT} 31	76	GND
34	HV_{OUT} 32	77	GND
35	HV_{OUT} 33	78	DIR
36	HV_{OUT} 34	79	V_{DD}
37	HV_{OUT} 35	80	Blanking
38	HV_{OUT} 36	81	CLK
39	HV_{OUT} 37	82	LE
40	HV_{OUT} 38	83	Data In/Out A
41	HV_{OUT} 39	84	Data In/Out A
42	HV_{OUT} 40	85	Data In/Out A
43	HV_{OUT} 41	86	Data In/Out A

HV78

Pin	Function	Pin	Function
1	HV_{OUT} 1	44	HV_{OUT} 42
2	HV_{OUT} 2	45	V_{PP}
3	HV_{OUT} 3	46	GND
4	HV_{OUT} 4	47	HV_{OUT} 43
5	HV_{OUT} 5	48	HV_{OUT} 44
6	HV_{OUT} 6	49	HV_{OUT} 45
7	HV_{OUT} 7	50	HV_{OUT} 46
8	HV_{OUT} 8	51	HV_{OUT} 47
9	HV_{OUT} 9	52	HV_{OUT} 48
10	HV_{OUT} 10	53	HV_{OUT} 49
11	HV_{OUT} 11	54	HV_{OUT} 50
12	HV_{OUT} 12	55	HV_{OUT} 51
13	HV_{OUT} 13	56	HV_{OUT} 52
14	HV_{OUT} 14	57	HV_{OUT} 53
15	HV_{OUT} 15	58	HV_{OUT} 54
16	HV_{OUT} 16	59	HV_{OUT} 55
17	HV_{OUT} 17	60	HV_{OUT} 56
18	HV_{OUT} 18	61	HV_{OUT} 57
19	HV_{OUT} 19	62	HV_{OUT} 58
20	HV_{OUT} 20	63	HV_{OUT} 59
21	HV_{OUT} 21	64	HV_{OUT} 60
22	HV_{OUT} 22	65	HV_{OUT} 61
23	GND	66	HV_{OUT} 62
24	V_{PP}	67	HV_{OUT} 63
25	HV_{OUT} 23	68	HV_{OUT} 64
26	HV_{OUT} 24	69	V_{PP}
27	HV_{OUT} 25	70	V_{PP}
28	HV_{OUT} 26	71	NC
29	HV_{OUT} 27	72	NC
30	HV_{OUT} 28	73	Data In/Out B
31	HV_{OUT} 29	74	Data In/Out B
32	HV_{OUT} 30	75	POL
33	HV_{OUT} 31	76	GND
34	HV_{OUT} 32	77	GND
35	HV_{OUT} 33	78	DIR
36	HV_{OUT} 34	79	V_{DD}
37	HV_{OUT} 35	80	Blanking
38	HV_{OUT} 36	81	CLK
39	HV_{OUT} 37	82	LE
40	HV_{OUT} 38	83	NC
41	HV_{OUT} 39	84	NC
42	HV_{OUT} 40	85	Data In/Out A
43	HV_{OUT} 41	86	Data In/Out A



Pad Coordinates in Microns

1	0; 0	22	1959.5; 2190
2	0;164	23	2115; 1476
3	0; 328	24	2115; 1312
4	0; 492	25	2115; 1148
5	0; 656	26	2115; 984
6	0; 820	27	2115; 820
7	0; 984	28	2115; 656
8	0; 1148	29	2115; 492
9	0; 1312	30	2115; 328
10	0; 1476	31	2115; 164
11	155.5; 2190	32	2115; 0
12	319.5; 2190	33	2056; -177
13	483.5; 2190	34	1741.5; -182
14	647.5; 2190	35	-1406; -177
15	811.5; 2190	36	1228.5; -177
16	975.5; 2190	37	1051; -177
17	1139.5; 2190	38	867.5; -177
18	1303.5; 2190	39	685; -177
19	1467.5; 2190	40	376.5; -182
20	1631.5; 2190	41	69; -177
21	1795.5; 2190		

Die Specifications

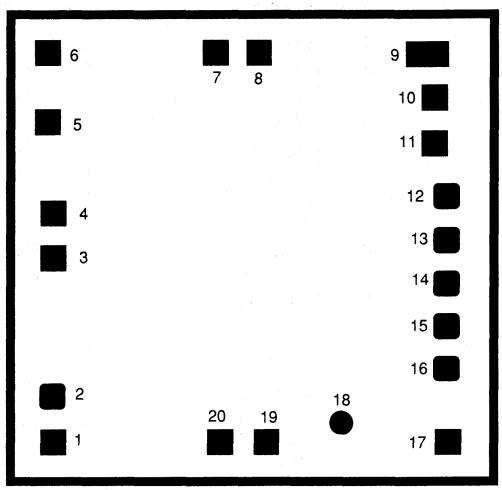
	mils	mm		
Die Size:	97 X 109	2.463 X 2.768	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 or equal
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		

HV83	
Pin	**Function**
1	HV_{OUT} 1
2	HV_{OUT} 2
3	HV_{OUT} 3
4	HV_{OUT} 4
5	HV_{OUT} 5
6	HV_{OUT} 6
7	HV_{OUT} 7
8	HV_{OUT} 8
9	HV_{OUT} 9
10	HV_{OUT} 10
11	HV_{OUT} 11
12	HV_{OUT} 12
13	HV_{OUT} 13
14	HV_{OUT} 14
15	HV_{OUT} 15
16	HV_{OUT} 16
17	HV_{OUT} 17
18	HV_{OUT} 18
19	HV_{OUT} 19
20	HV_{OUT} 20
21	HV_{OUT} 21
22	HV_{OUT} 22
23	HV_{OUT} 23
24	HV_{OUT} 24
25	HV_{OUT} 25
26	HV_{OUT} 26
27	HV_{OUT} 27
28	HV_{OUT} 28
29	HV_{OUT} 29
30	HV_{OUT} 30
31	HV_{OUT} 31
32	HV_{OUT} 32
33	OE
34	Data In
35	LE
36	V_{DD}
37	V_{PP}
38	GND
39	CLK
40	NC
41	Data Out

HV84	
Pin	**Function**
1	HV_{OUT} 32
2	HV_{OUT} 31
3	HV_{OUT} 30
4	HV_{OUT} 29
5	HV_{OUT} 28
6	HV_{OUT} 27
7	HV_{OUT} 26
8	HV_{OUT} 25
9	HV_{OUT} 24
10	HV_{OUT} 23
11	HV_{OUT} 22
12	HV_{OUT} 21
13	HV_{OUT} 20
14	HV_{OUT} 19
15	HV_{OUT} 18
16	HV_{OUT} 17
17	HV_{OUT} 16
18	HV_{OUT} 15
19	HV_{OUT} 14
20	HV_{OUT} 13
21	HV_{OUT} 12
22	HV_{OUT} 11
23	HV_{OUT} 10
24	HV_{OUT} 9
25	HV_{OUT} 8
26	HV_{OUT} 7
27	HV_{OUT} 6
28	HV_{OUT} 5
29	HV_{OUT} 4
30	HV_{OUT} 3
31	HV_{OUT} 2
32	HV_{OUT} 1
33	OE
34	Data In
35	LE
36	V_{DD}
37	V_{PP}
38	GND
39	CLK
40	NC
41	Data Out

HV87	
Pin	**Function**
1	HV_{OUT} 1
2	HV_{OUT} 2
3	HV_{OUT} 3
4	HV_{OUT} 4
5	HV_{OUT} 5
6	HV_{OUT} 6
7	HV_{OUT} 7
8	HV_{OUT} 8
9	HV_{OUT} 9
10	HV_{OUT} 10
11	HV_{OUT} 11
12	HV_{OUT} 12
13	HV_{OUT} 13
14	HV_{OUT} 14
15	HV_{OUT} 15
16	HV_{OUT} 16
17	HV_{OUT} 17
18	HV_{OUT} 18
19	HV_{OUT} 19
20	HV_{OUT} 20
21	HV_{OUT} 21
22	HV_{OUT} 22
23	HV_{OUT} 23
24	HV_{OUT} 24
25	HV_{OUT} 25
26	HV_{OUT} 26
27	HV_{OUT} 27
28	HV_{OUT} 28
29	HV_{OUT} 29
30	HV_{OUT} 30
31	HV_{OUT} 31
32	HV_{OUT} 32
33	Blanking
34	Data In
35	LE
36	V_{DD}
37	V_{PP}
38	GND
39	CLK
40	POL
41	Data Out

HV88	
Pin	**Function**
1	HV_{OUT} 32
2	HV_{OUT} 31
3	HV_{OUT} 30
4	HV_{OUT} 29
5	HV_{OUT} 28
6	HV_{OUT} 27
7	HV_{OUT} 26
8	HV_{OUT} 25
9	HV_{OUT} 24
10	HV_{OUT} 23
11	HV_{OUT} 22
12	HV_{OUT} 21
13	HV_{OUT} 20
14	HV_{OUT} 19
15	HV_{OUT} 18
16	HV_{OUT} 17
17	HV_{OUT} 16
18	HV_{OUT} 15
19	HV_{OUT} 14
20	HV_{OUT} 13
21	HV_{OUT} 12
22	HV_{OUT} 11
23	HV_{OUT} 10
24	HV_{OUT} 9
25	HV_{OUT} 8
26	HV_{OUT} 7
27	HV_{OUT} 6
28	HV_{OUT} 5
29	HV_{OUT} 4
30	HV_{OUT} 3
31	HV_{OUT} 2
32	HV_{OUT} 1
33	Blanking
34	Data In
35	LE
36	V_{DD}
37	V_{PP}
38	GND
39	CLK
40	POL
41	Data Out



Pad Coordinates in Microns

1	0; 0
2	-1; 178
3	-1; 723.5
4	-.5; 900.5
5	-15.5; 1253
6	-15.5; 1526.5
7	630.5; 1522
8	798.5; 1522.5
9	1461.75; 1522
10	1494.5; 1347
11	1494.5; 1172
12	1539.5; 965
13	1539.5; 797
14	1539.5; 629
15	1539.5; 461
16	1539.5; 293
17	1539.5; 5
18	1123; 79.5
19	829; 0
20	649; 0

HV91

Pin	Function	Pin	Function
1	Comp	11	Output
2	N/C	12	N/C
3	Reset	13	N/C
4	Shut down	14	N/C
5	V_{REF}	15	N/C
6	Discharge	16	N/C
7	OSC In	17	Sense
8	OSC Out	18	+ V_{IN}
9	V_{CC}	19	BIAS
10	-V_{IN}	20	Feedback

Die Specifications

	mils	mm		
Die Size:	76 X 74	1.930 X 1.879	Back Side Metal:	None
Die Thickness:	20 ±1	0.50 ±0.02	Die Attach Material:	Epoxy Ablestick 84-1 LMIS
Bond Pad Size:	4 X 4	0.10 X 0.10	Bond Pad Metal:	Al/Si
Bond Wire Size:	1.3	0.03		

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